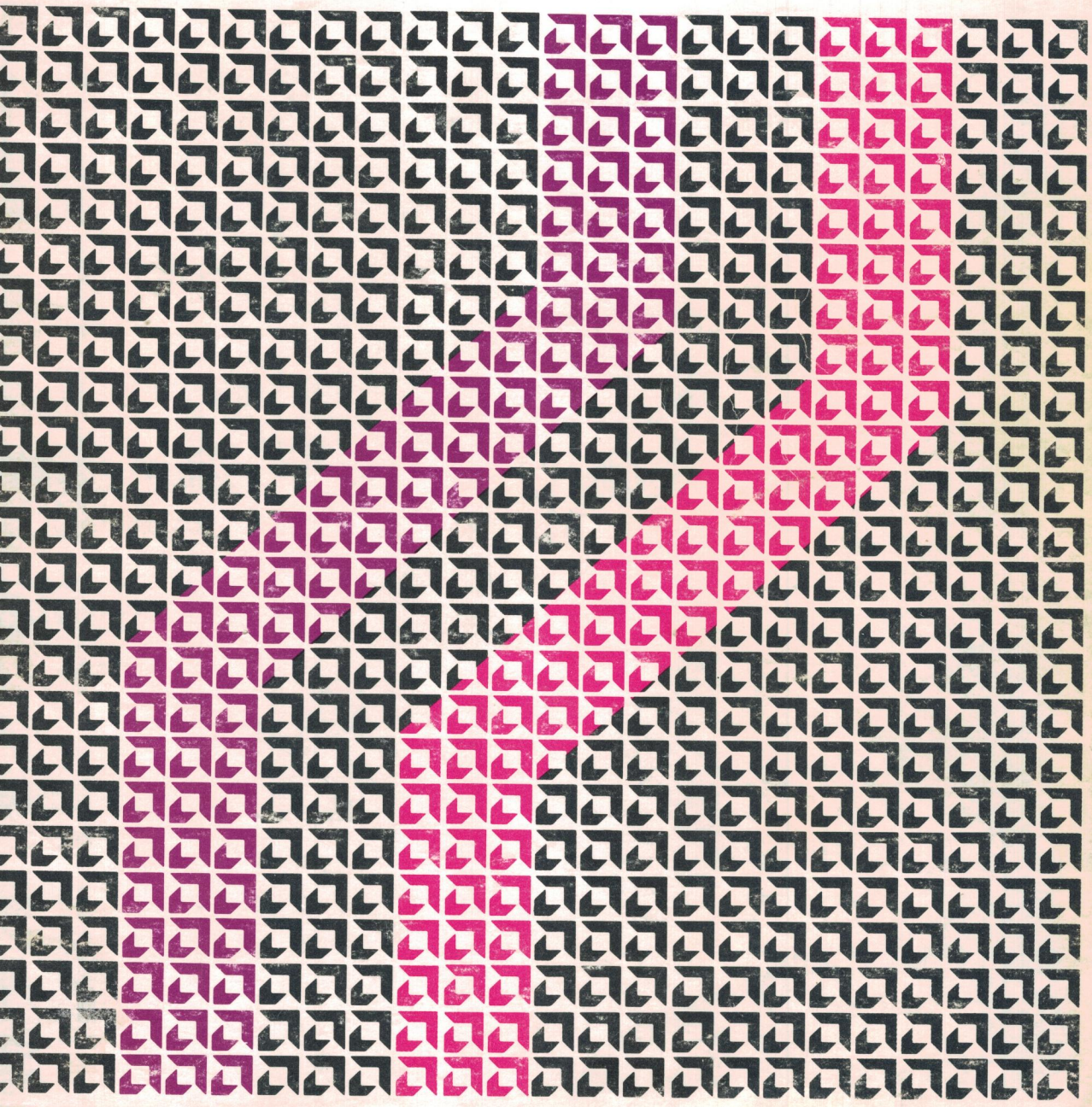


Advanced
Micro
Devices, Inc.

Schottky And
Low-Power
Schottky
Data Book







Advanced Micro Devices

Schottky and Low-power Schottky Data Book Including Digital Signal Processing Handbook

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SCHOTTKY AND LOW-POWER SCHOTTKY FUNCTIONAL SELECTOR GUIDE

This guide divides the AMD Low-Power Schottky and Schottky TTL Product Line by function into three basic performance categories indicated by the examples below.

1. High-Performance, Low-Power Schottky Ex. 25LS174 Six Bit Register. $f_{max} = 40\text{MHz}$ (Min.)

2. Standard Low-Power Schottky
Ex. 74LS174 Six Bit Register. $f_{max} = 30\text{MHz}$ (Min.)

3. High-Speed Schottky
Ex. 74S174 Six Bit Register. $f_{max} = 75\text{MHz}$ (Min.)

DESCRIPTION	HIGH-PERFORMANCE LOW-POWER SCHOTTKY	STANDARD LOW-POWER SCHOTTKY	HIGH-SPEED SCHOTTKY
DECADE (BCD) COUNTERS			
Asynchronous Clear, Synchronous Preset	25LS160A	54/74LS160A	54/74S160/93S10
Synchronous Clear, Synchronous Preset	25LS162A	54/74LS162A	
Up-Down, Synchronous Preset	25LS168A	54/74LS168A	
Up-Down, Asynchronous Preset, Single Clock	25LS190	54/74LS190	
Up-Down, Asynchronous Preset, Dual Clock	25LS192	54/74LS192	
Up-Down, Synchronous Preset, Three-State	25LS2568		
BINARY HEXADECIMAL COUNTERS			
Asynchronous Clear, Synchronous Preset	25LS161A	54/74LS161A	54/74S161/93S16
Synchronous Clear, Synchronous Preset	25LS163A	54/74LS163A	
Up-Down, Synchronous Preset	25LS169A	54/74LS169A	
Up-Down, Asynchronous Preset, Single Clock	25LS191	54/74LS191	
Up-Down, Asynchronous Preset, Dual Clock	25LS193	54/74LS193	
Up-Down, Synchronous Preset, Three-State	25LS2569		
DECODER/DEMULTIPLEXERS			
One-of-Ten Decoder/Demultiplexer, Polarity Control	25LS2537		
One-of-Eight Decoder/Demultiplexer	25LS138	54/74LS138	54/74S138
One-of-Eight Decoder/Demultiplexer with Control Storage	25LS2536		
Dual One-of-Four Decoder/Demultiplexer	25LS139	54/74LS139	54/74S139/93S21
One-of-Eight Decoder/Demultiplexer, Polarity Control	25LS2538		
Dual One-of-Four Decoder/Demultiplexer, Polarity Control	25LS2539		
MULTIPLEXERS			
Eight-Input Multiplexer	25LS151	54/74LS151	54/74S151
Eight-Input Multiplexer with Control Storage	25LS2535		
Three-State Eight-Input Multiplexer	25LS251	54/74LS251	54/74S251
Dual Four-Input Multiplexer	25LS153	54/74LS153	54/74S153
Three-State Dual Four-Input Multiplexer	25LS253	54/74LS253	54/74S253
Quad Two-Input Multiplexer; Non-Inverting	25LS157	54/74LS157	54/74S157/93S22
Three-State Quad Two-Input Multiplexer; Non-Inverting	25LS257	54/74LS257	54/74S257
Quad Two-Input Multiplexer; Inverting	25LS158	54/74LS158	54/74S158
Three-State Quad Two-Input Multiplexer; Inverting	25LS258	54/74LS258	54/74S258
MONOSTABLE (ONE-SHOT)			
Dual Retriggerable, Resettable Monostable Multivibrator			26S02
OPERATORS (ALU, MULTIPLIER, PRIORITY ENCODER, etc.)			
Four by Two Two's Complement Multiplier			25S05
Four-Bit, Four-Way Shifter			25S10/54/74S350
Four-Bit ALU/Function Generator	25LS181	54/74LS181	54/74S181
Four-Bit ALU/Function Generator	25LS2517		
Four-Bit ALU/Function Generator	25LS381	54/74LS381	
Four-Bit Parallel Accumulator	25LS281	54/74LS281	
Priority Encoder, Eight Line to Three Line	25LS148	54/74LS148	
Four-Bit Serial Adder/Subtractor	25LS15		
Priority Encoder, Three State	25LS2513		
Eight by One Serial/Parallel Two's Complement Multiplier	25LS14		
Eight-Bit by Eight-Bit Multiplier/Accumulator	25LS2516		
Eight-Bit Comparator	25LS2521		
Eight-Bit Registered Comparator	25LS2524		
System Clock Generator and Driver	25LS2525		

FUNCTIONAL SELECTOR GUIDE (Cont.)

DESCRIPTION	HIGH-PERFORMANCE LOW-POWER SCHOTTKY	STANDARD LOW-POWER SCHOTTKY	HIGH-SPEED SCHOTTKY
PARITY CHECKER/GENERATORS			
Nine-Input Parity Checker/Generator			82S62
Twelve-Input Parity Checker/Generator			93S48
REGISTERS			
Four-Bit Register with Common Clock Enable	25LS08	54/74LS379	25S08/54/74S379
Four-Bit Register with Two-Input Multiplexers on Inputs	25LS09	54/74LS399	25S09/54/74S388
Four-Bit Register with Standard and Three-State Outputs	25LS2518		25S18/54/74S388
Four-Bit, Two-Output Three-State Register	25LS2519		
Four-Bit Register with Common Clear	25LS175	54/74LS175	54/74S175
Four-Bit Register; Shift Right, Left or Parallel Load	25LS194A	54/74LS194A	54/74S194
Four-Bit Register; Shift Right or Parallel Load	25LS195A	54/74LS195A	54/74S195
Six-Bit Register with Common Clock Enable	25LS07	54/74LS378	25S07/54/74S378
Six-Bit Register with Common Clear	25LS174	54/74LS174	54/74S174
Eight-Bit, Serial-In, Parallel-Out Register	25LS164	54/74LS164	
Eight-Bit Shift/Storage Register; Synchronous Clear	25LS23		
Eight-Bit Shift/Storage Register; Asynchronous Clear	25LS299	54/74LS299	
Eight-Bit Shift-Storage Register with Sign Extend	25LS22		
Octal D-Type Register, Common Clear	25LS273B	54/74LS273B	
Octal Transparent Latch (Three State, non-inverting)	25LS373	54/74LS373	*54/74S373
Octal Transparent Latch (Three-state, inverting)	*25LS533	*54/74LS533	*54/74S533
Octal D-Type Register (Three State, non-inverting)	25LS374	54/74LS374	*54/74S374
Octal D-Type Register (Three-state, inverting)	*25LS534	*54/74LS534	*54/74S534
Octal D-Type Register, Common Enable	25LS377B	54/74LS377B	
Octal D-Type Register, Common Enable and Clear, Three-State	25LS2520		
BUS INTERFACE			
Quad Bus Transceiver, Inverting (100mA)			26S10
Quad Bus Transceiver, Non-Inverting (100mA)			26S11
Quad Bus Transceiver, Inverting	25LS242	54/74LS242	54/74S242
Quad Bus Transceiver, Non-Inverting	25LS243	54/74LS243	54/74S243
Quad Open-Collector Bus Transceiver			26S12/12A
Quad Three-State Bus Transceiver (Inverting)			8TS12/12A
Quad Three-State Bus Transceiver (Non-Inverting)			8T28
Quad Two I/P Transceiver with Three-State Receiver (O.C.)	2905		
Quad Two I/P Transceiver with Parity (O.C.)	2906		
Quad Two I/P Transceiver with Parity (O.C.)	2907		
Quad Two I/P Transceiver with Three-State Receiver (Three-State)	2915A		
Quad Two I/P Transceiver with Parity (Three-State)	2916A		
Quad Two I/P Transceiver with Parity (Three-State)	2917A		
Octal Bus Driver, Inverting	25LS240	54/74LS240	54/74S240
Octal Bus Driver, Non-Inverting (Complementary G, G inputs)	25LS241	54/74LS241	54/74S241
Octal Bus Driver, Non-Inverting	25LS244	54/74LS244	54/74S244
Octal Bus Driver, Low-Power.	71/81LS95		
Octal Bus Driver, Low-Power, Inv.	71/81LS96		
Octal Bus Driver, Low-Power.	71/81LS97		
Octal Bus Driver, Low-Power, Inv.	71/81LS98		
Octal Bidirectional Bus Transceiver	8304		

* In development.

Introduction to Low-Power Schottky

- **Comparison between Am25LS and 54LS/74LS** 2-2
- **Am25LS-54LS/74LS Low-Power Schottky Cross Reference** 2-4
- **Designers Guide to High Performance
Low-Power Schottky** 2-6
- **Reliability Report** 2-20

ADVANCED MICRO DEVICES SCHOTTKY AND LOW-POWER SCHOTTKY MSI

Advanced Micro Devices offers a complete line of Schottky and Low-Power Schottky MSI products. On the following pages are a selector guide for these products and brief data on several of the most useful parts. For complete data refer to our Schottky and Low-Power Schottky Data Book.

Advanced Micro Devices offers two LS Logic families.

- Am25LS – High Performance
- Am54/74LS – Standard Performance

Similar elements of both families are described on the same data sheet. Key parameters are compared below.

All Advanced Micro Devices' products are manufactured to the quality assurance requirements of MIL-STD-883, Level C. According to Handbook 217B published by the Rome Air Development Center, the Air Force's principal authority on component reliability, Level C integrated circuits are up to ten times more reliable than normal industry commercial parts. Even if you don't need the performance features of Am25LS, you can buy our versions of 54/74LS devices with the assurance that they are manufactured to the stringent quality standards of MIL-STD-883.

Am25LS IMPROVED PERFORMANCE

• Noise Margin

At $I_{OL} = 8\text{mA}$, Am25LS guarantees $V_{OL} = 0.45\text{V}$ compared to 0.50V for 54/74LS.

• Fan Out

Over the military temperature range, Am25LS is specified at $I_{OL} = 8\text{mA}$, for a F.O. of 22 (8mA/0.36mA). 54LS is guaranteed at $I_{OL} = 4\text{mA}$ only, for F.O. = 11 (4mA/0.36mA).

• I_{SC} (Max.)

Am25LS has I_{SC} upper limit controlled to 85mA (Max.).

• Speed

In this example, Am25LS164 has worst case clock to output delay specified up to 45% faster and f_{MAX} at more than 40% faster than 54/74LS164: Most Am25LS devices offer similar improvements.

10X
MORE RELIABLE

50mV MORE
NOISE MARGIN

TWICE THE
FAN-OUT

REDUCED SUPPLY
CURRENT SPIKING

FASTER

SWITCHING SPEED SPECIFIED AT TEMPERATURE AND POWER SUPPLY EXTREMES

The switching speeds of all new Am25LS devices are now being specified at:

- Full 50pF load
- Over the operating temperature range
 - Military -55°C to $+125^{\circ}\text{C}$
 - Commercial 0°C to $+70^{\circ}\text{C}$
- Over the operating power supply range
 - Military $5.0\text{V} \pm 10\%$
 - Commercial $5.0\text{V} \pm 5\%$

MORE FULLY
SPECIFIED

PRICE

Most Am25LS device list prices are the same or less than the equivalent 54/74LS standard performance device.

Am25LS164 • Am54LS/74LS164

8-Bit Serial-In, Parallel-Out Shift Register

DISTINCTIVE CHARACTERISTICS

- Gated serial inputs
- Asynchronous clear
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL} at $I_{OL} = 8\text{mA}$
 - Typical fan-out over military range
 - 440 μA source current at HIGH output
- 100% product assurance testing to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

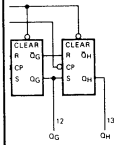
The Am25LS164 and Am54LS/74LS164 are eight-bit, serial in/parallel out shift registers built using advanced Low-Power Schottky processing. A gated input provides enable/disable control over incoming data such that the data can be entered or logic zeros can be entered into the register.

An asynchronous clear input can be used to simultaneously clear the eight flip-flops in the device. When the clear input is LOW, all internal flip-flops are forced LOW independent of the clock input. An incoming data bit is entered into the Q_0 flip-flop and the data in all internal flip-flops is shifted right on the LOW-to-HIGH transition of the clock input.

The Am54LS/74LS164 is a standard performance version of the Am25LS164. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAM

Am25LS164



ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25V
 MIL $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)			Units
			Min.	Typ.	Max.	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH}$ or V_{IL}	2.5	3.4	3.4	Volts
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4.0\text{mA}$	0.25	0.4	Volts
			$I_{OL} = 8.0\text{mA}$	0.35	0.45	Volts
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0		Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		0.7	Volts	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$		-1.5	Volts	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	Clock, Clear		-0.36	mA
			A, B		-0.4	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$		20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$		0.1	mA	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15	-85	mA	
I_{CC}	Power Supply Current (Note 4)					

Notes: 1. For conditions shown as MIN. or MAX.
 2. Typical limits are at $V_{CC} = 5.0\text{V}, 25^\circ\text{C}$
 3. Not more than one output should be shorted with outputs open, serial input measured with outputs open, serial input

Am54LS/74LS164

Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)			Units
			Min.	Typ.	Max.	
I_{OH}	Output HIGH Current	$V_{CC} = \text{MAX.}, V_{OH} = 2.7\text{V}$	COM'L	2.5	3.4	Volts
			MIL	2.7	3.4	Volts
I_{OL}	Output LOW Current	$V_{CC} = \text{MAX.}, V_{OL} = 0.4\text{V}$	All, $I_{OL} = 4.0\text{mA}$	0.25	0.4	Volts
			74LS only, $I_{OL} = 8.0\text{mA}$	0.35	0.5	Volts
V_{OH}	Output HIGH Voltage	Clock, HIGH		2.0		Volts
					0.7	Volts
				0.8	Volts	
				-1.5	Volts	
				-0.4	mA	
				20	μA	
				0.1	mA	
				-100	mA	
				27	mA	

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}, V_{CC} = 5.0\text{V}$)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Clock to Output	14	20	17	27	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$		
t_{PHL}	Clear to Output	11	22	2	32	ns			
t_{PHL}	Clear to Output	17	19	29	20	36	ns		
t_{pw}	Clock or Clear	10		15		ns			
t_s	Data	5.0		5.0		ns			
t_h	Data	5.0		5.0		ns			
t_s	Clear Recovery Time	20				ns			
f_{max}	Maximum Clock Frequency	35	42	25	36	MHz			

Am25LS ONLY SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to Output	26	30	30	30	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}	Clear to Output	30	35	35	42	ns	
t_{PHL}	Clear to Output	22	25	25	25	ns	
t_{pw}	Clock or Clear	13	15	15	15	ns	
t_s	Data	5	5	5	5	ns	
t_h	Data	25	30	30	30	ns	
t_s	Clear Recovery Time	25	20	20	20	MHz	
f_{max}	Maximum Clock Frequency	25	20	20	20	MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

Am25LS•Am54LS/74LS CROSS REFERENCE GUIDE

Advanced Micro Devices offers both Am25LS, High Performance, and 54LS/74LS Standard Performance, low-power Schottky families. Am25LS devices may be substituted for 54LS/74LS devices as shown in the table below.

Products with different numbers corresponding to the similar Am25LS and 54LS/74LS functions are Texas Instruments second source part numbers to Advanced Micro Devices products.

Am25LS HIGH PERFORMANCE LS	Am54/74LS STANDARD LS	DESCRIPTION	PACKAGE PINS
AM25LS07	AM54/74LS378	Six-Bit Register; Common Enable	16
AM25LS08	AM54/74LS379	Four-Bit Register; Common Enable	16
AM25LS09	AM54/74LS399	Four-Bit Register; Multiplexed Inputs	16
AM25LS14	AM54/74LS384	Eight-Bit Serial/Parallel Two's Complement Multiplier	16
AM25LS15	AM54/74LS385	Four-Bit Serial/Parallel Adder Subtractor	20
AM25LS22	AM54/74LS322	Eight-Bit Serial/Parallel Register; Sign Extend	20
AM25LS23	AM54/74LS323	Eight-Bit Universal Shift Register; Synchronous Clear	20
AM25LS138	AM54/74LS138	One-of-Eight Decoder/Demultiplexer	16
AM25LS139	AM54/74LS139	Dual One-of-Four Decoder/Demultiplexer	16
AM25LS148	AM54/74LS148	Priority Encoder; Eight-Line to Three-Line	16
AM25LS151	AM54/74LS151	Eight-Input Multiplexer	16
AM25LS153	AM54/74LS153	Dual-Four-Input Multiplexer	16
AM25LS157	AM54/74LS157	Quad Two-Input Multiplexer; Non-Inverting	16
AM25LS158	AM54/74LS158	Quad Two-Input Multiplexer; Inverting	16
AM25LS160A	AM54/74LS160A	Synchronous BCD Decade Counter; Asynchronous Clear	16
AM25LS161A	AM54/74LS161A	Synchronous Four-Bit Binary Counter; Asynchronous Clear	16
AM25LS162A	AM54/74LS162A	Synchronous BCD Decade Counter; Synchronous Clear	16
AM25LS163A	AM54/74LS163A	Synchronous Four-Bit Binary Counter; Synchronous Clear	16
AM25LS164	AM54/74LS164	Eight-Bit Serial-In, Parallel-Out Shift Register	14
AM25LS168A	AM54/74LS168A	Synchronous BCD Decade Up-Down Counter; Programmable	16
AM25LS169A	AM54/74LS169A	Synchronous Four-Bit Binary Up-Down Counter; Programmable	16
AM25LS174	AM54/74LS174	Six-Bit Register; Common Clear	16
AM25LS175	AM54/74LS175	Quad Register; Common Clear	16
AM25LS181	AM54/74LS181	Four-Bit ALU/Function Generator	24
AM25LS190	AM54/74LS190	BCD Decade Up-Down Counter; Down-Up Mode Control	16
AM25LS191	AM54/74LS191	Four-Bit Binary Up-Down Counter; Down-Up Mode Control	16
AM25LS192	AM54/74LS192	BCD Decade Up-Down Counter; Dual Clocks	16
AM25LS193	AM54/74LS193	Four-Bit Binary Up-Down Counter; Dual Clocks	16
AM25LS194A	AM54/74LS194A	Four-Bit Register; Shift Right, Left or Parallel Load	16
AM25LS195A	AM54/74LS195A	Four-Bit Register; Shift Right or Parallel Load	16
AM25LS240	AM54/74LS240	Octal Bus Driver; Inverting, Three State Outputs	20
AM25LS241	AM54/74LS241	Octal Bus Driver; Non-Inverting, Three State Outputs (G, G inputs)	20
AM25LS242	AM54/74LS242	Quad Bus Transceiver; Inverting	14
AM25LS243	AM54/74LS243	Quad Bus Transceiver; Non-Inverting	14
AM25LS244	AM54/74LS244	Octal Bus Driver; Non-Inverting, Three State Outputs	20
AM25LS251	AM54/74LS251	Eight-Input Multiplexer; Three State Outputs	16
AM25LS253	AM54/74LS253	Dual Four-Input Multiplexer; Three State Outputs	16
AM25LS257	AM54/74LS257	Quad Two-Input Multiplexer; Non-Inverting, Three State Outputs	16
AM25LS258	AM54/74LS258	Quad Two-Input Multiplexer; Inverting, Three State Outputs	16
AM25LS273	AM54/74LS273	Octal D-Register; Common Clear	20
*AM25LS281	*AM54/74LS281	Four-Bit Parallel Accumulator	24
AM25LS299	AM54/74LS299	Eight-Bit Universal Shift Register, Asynchronous Clear	20
-	AM54/74LS322	See Am25LS22	20
-	AM54/74LS323	See Am25LS23	20
AM25LS373	AM54/74LS373	Octal Transparent Latch; Three State Outputs	20
AM25LS374	AM54/74LS374	Octal D-Register; Three State Outputs	20
AM25LS377	AM54/74LS377	Octal D-Register; Common Enable	20
AM25LS378	AM54/74LS378	Six-Bit Register, Common Enable (25LS07)	16
AM25LS379	AM54/74LS379	Four-Bit Register, Common Enable (25LS08)	16
AM25LS381	AM54/74LS381	Four-Bit ALU/Function Generator (20 pin 25LS181)	20

* In development.

Am25LS•Am54LS/74LS CROSS REFERENCE GUIDE (Cont.)

Am25LS HIGH PERFORMANCE LS	Am54/74LS STANDARD LS	DESCRIPTION	PACKAGE PINS
—	AM54/74LS382	See Am25LS2517	20
—	AM54/74LS384	See Am25LS14	16
—	AM54/74LS385	See Am25LS15	20
—	AM54/74LS388	See Am25LS2518	16
AM25LS399	AM54/74LS399	Four-Bit Register, Multiplexed Inputs (25LS09)	16
—	*AM54/74LS533	Inverting version of Am25/54/74LS373	20
—	*AM54/74LS534	Inverting version of Am25/54/74LS374	20
—	AM54/74LS568	See Am25LS2568	20
—	AM54/74LS569	See Am25LS2569	20
—	AM54/74LS668	Slow Version of Am25/54/74LS168A	16
—	AM54/74LS669	Slow Version of Am25/54/74LS169A	16
AM25LS2513	—	Priority Encoder; Three State Outputs, Eight-Line to Three-Line	20
AM25LS2516	—	Eight-Bit by Eight-Bit Serial/Parallel Multiplier/Accumulator	40
AM25LS2517	—	Four-Bit ALU/Function Generator; Overflow Detection	20
AM25LS2518	AM54/74LS388	Quad Register with Standard and Three State Outputs	16
AM25LS2519	—	Quad Register with Dual Three State Outputs	20
AM25LS2520	—	Octal D-Register; Common Clear and Enable, Three State Outputs	22
AM25LS2521	—	Eight-Bit Comparator	20
*AM25LS2524	—	Registered Comparator	20
*AM25LS2525	—	System Clock Generator and Driver	20
AM25LS2535	—	Eight-Bit Multiplexer; Control Storage	20
AM25LS2536	—	Eight-Bit Decoder; Control Storage	20
AM25LS2537	—	One-of-Ten Decoder; Three State Outputs	20
AM25LS2538	—	One-of-Eight Decoder; Three State Outputs	20
AM25LS2539	—	Dual One-of-Four Decoder; Three State Outputs	20
AM25LS2568	—	BCD Decade Up-Down Counter; Three State Outputs	20
AM25LS2569	—	Four-Bit Binary Up-Down Counter; Three State Outputs	20

*In development.

DESIGNER'S GUIDE TO HIGH PERFORMANCE LOW-POWER SCHOTTKY LOGIC

By David A. Laws and Roy J. Levy.

1.

THE NEW STANDARD LOGIC

Low-power Schottky TTL integrated circuits are now firmly established as the standard logic configuration for new high performance system designs. They have essentially entirely replaced standard "gold-doped" TTL devices in all applications.

In addition, they have relegated the other logic families to specialized needs where the ultimate in high speed (ECL) or low power for battery operated operation (CMOS) is mandatory.

This wide acceptance has been achieved because LS offered all of the important features of the earlier TTL families with two significant advantages:

- LS circuits provide performance equal to that of standard TTL at between 20% and 50% of the power requirements. As a result, considerable system cost savings have been made in bulky power supplies and fans.
- LS technology allows more complex designs to be fabricated on a given die size. A far wider selection of systems oriented MSI and LSI functions have therefore been developed in the LS family.

Additional factors in their popularity is that the devices are implemented with the same technology, and are therefore totally compatible with the LSI bit-slice processors and supporting memories which today form the heart of most new high speed designs. Users of LS devices have been able to exploit these features to improve the performance and enhance the functional capability of their systems. In many cases this has been achieved at a lower total cost.

Advanced Micro Devices is a leading supplier of low-power Schottky MSI and LSI devices. Two basic families of product are offered:

AM54/74LS Series

- Typical tpd 10ns/gate at 2mW
- Typical Register fmax = 40MHz

Pin for pin and electrical alternate source devices to the standard performance LS logic family.

AM25LS Series

- Typical tpd 5ns/gate at 2mW
- Typical Register fmax = 65MHz

Advanced Micro Devices' proprietary high performance LS logic family. This includes both original designs and enhanced specification versions of the AM54/74LS devices. Improvements include twice the fan-out over the military temperature range, higher noise margin and faster switching speeds.

The AM25LS improved performance devices are offered by Raytheon Semiconductor and identified by 25LS part numbers. Equivalent Fairchild and Motorola 9LS functions will come close to meeting AM25LS switching speeds on certain products.

The AM25LS proprietary designs have been carefully chosen to improve operation and reduce the cost of building high performance digital systems. A good example is the set of AM25LS14, 15 and 22 digital signal processing elements. Fairchild, Motorola and Texas Instruments have announced plans to alternate source many of the new Advanced Micro Devices' designs.

Both the Am25LS and the Am54LS/74LS families can be freely intermixed. Together with the Am2900 series of bipolar microprocessor functions they will satisfy most of the design requirements of today's advanced systems.

THE SCHOTTKY DIODE STRUCTURE

The major components of switching delays in digital integrated circuits are listed in Figure 1. One of the most significant of these is the storage time constant of a transistor driven into saturation T_s . Standard TTL circuits minimize this parameter with a process technique known as gold doping. This increases the rate of recombination of charge stored in the base region.

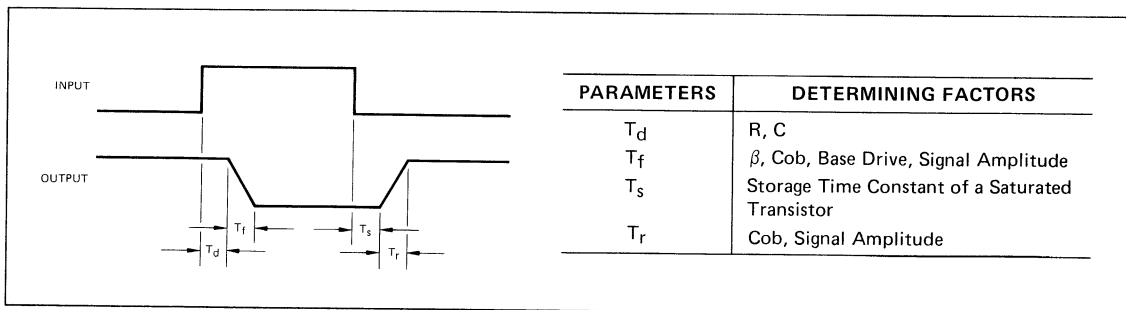


Figure 1. Major Causes of Propagation Delay.

The desired result of improved speed is achieved. Unfortunately it also reduces available design β at low temperatures and is marginally effective when hot. This results in lowered performance over the full military temperature range.

The development of the Schottky diode provides a more effective solution. A feature of the Schottky diode is its lower forward voltage at a given current level compared to a diffused (P-N) diode of the same area, Figure 2. Connecting a Schottky diode between the base and collector of a transistor, Figure 3, will shunt excess base current drive from the base to the collector, once the collector drops to a low enough voltage to forward bias the Schottky. This prevents the build up of stored charge and eliminates the T_s component of the delay.

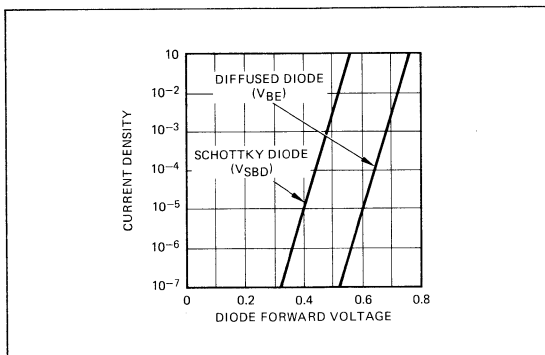


Figure 2. Comparison of V_F for Schottky and Diffused Diodes.

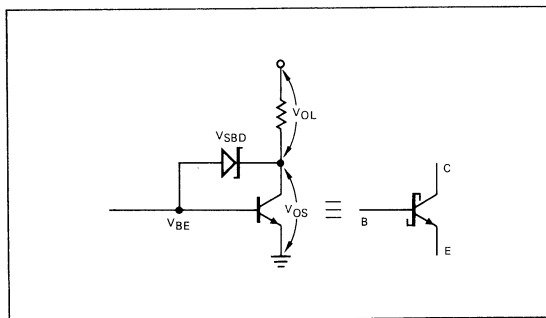


Figure 3. Schottky Clamped Transistor and its Conventional Circuit Symbol.

A Schottky diode is formed at a metal to semiconductor junction when the semiconductor doping is at the level normally found in the collector region of TTL devices. A Schottky-clamped transistor is constructed by extending the metal contact for the base region over the collector as shown in Figure 4. The same metallization structure forms a simple ohmic contact at the base, collector and emitter contact windows because of the higher doping levels in the silicon at these locations.

The selection of the forward voltage drop across the Schottky diode, V_{SBD} , is a compromise between a high value to insure a minimum V_{OL} but low enough to prevent charge storage in the base. Platinum silicide Schottky diodes provide this optimum voltage drop. Platinum is deposited and platinum-silicide is formed by sintering and annealing. As aluminum has a high affinity for silicon, in order to prevent the aluminum interconnect metallization from diffusing through the platinum material, with resulting lower V_{SBD} , a barrier of tungsten-titanium is evaporated after the platinum and before the aluminum metallization. This structure has been extensively evaluated and proven to have excellent reliability characteristics. It is now widely employed in the manufacture of Schottky devices. Reliability data is available from Advanced Micro Devices on request.

CHARACTERISTICS OF SCHOTTKY DEVICES

The primary reason for the development of Schottky devices was to improve AC (switching) performance and the first integrated circuits to employ this technique offered propagation delays as fast as 3ns. However, their fast rise and fall times and high power requirements have restricted their application to highest performance systems. More recently it was realized that the technique could be used to decrease the charging current required to achieve the 10ns speed specification of standard TTL gates. This insures considerably lower operating power requirements. The resulting family of devices are known as Low-Power Schottky (LS) circuits.

While the low current characteristics of LS devices are extremely important, other features of Schottky devices have contributed significantly to improved overall performance;

- Improved yield can be obtained to higher β specifications which reduces the variation of a.c. performance at low temperatures.
- Elimination of the marginal effect of gold doping at high temperature improves switching speed at the upper end.
- PNP transistors with useful β can now be fabricated. Since they reduce input load current requirements, they can be employed on inputs where loading is critical.

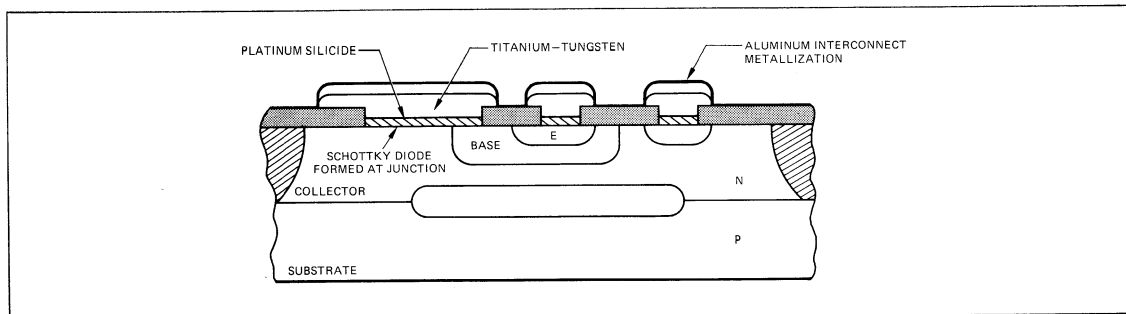


Figure 4. Schottky Diode Clamped Transistor Structure.

2

- The shallow epitaxial layers employed (around $3.5\mu\text{m}$) considerably reduce on chip capacitance and series resistance. This is a significant contributor to improved speed performance at low-power.
- Other improvements in general circuit design flexibility include improved control over internal waveform amplitudes, lower junction leakage currents and location of parasitic capacitances at low impedance nodes.

LOW-POWER SCHOTTKY FAMILIES

The first application of the low power technology to a commercially available product was to redesign the most popular elements of the standard, gold-doped 54/74 TTL family in LS. This provided a set of functions pin-for-pin and speed compatible with the earlier TTL parts, but requiring as little as 20% of the power. The basic gate design for a 54LS/74LS element is shown in Figure 5. This offers a typical propagation delay of 10ns at 2mW power dissipation. Similar improvements have been made in power requirements for flip-flops and MSI functions.

This LS family offers many advantages to the system designers over the older standard TTL functions.

- Lower supply currents permit the use of smaller, lower cost power supplies.
- Reduced power dissipation generates less heat and simplifies cooling needs and allows increased board packing density.
- Lower on-chip operating temperatures decrease IC failure rates, thus improving system reliability.
- Lower operating currents reduce output spiking, leading to a decrease in noise generation and associated system problems.
- As the input load current requirements of Low-Power Schottky are only 25% of standard TTL, the new circuits are easier to interface with MOS elements, such as memories and microprocessors.
- Provided input and output loading rules are obeyed, as the functions and pin-outs are identical to those of the earlier TTL families, it is easy to upgrade existing systems.

In addition, no retraining of personnel is necessary before proceeding with a new design using these improved circuits as most engineers are already familiar with the logic functions and capabilities of TTL.

Later improvements in process technology and design techniques have led to what is essentially a second generation of LS devices. Generally described as high-performance LS, these products maintain the same power requirements as 54LS/74LS but offer such improvements as:

- Up to 50% faster speed
- Improved DC noise margin (50mV at full drive)
- Twice the fan-out over the military temperature range

The Advanced Micro Devices' Am25LS Family combines all these high-performance features into products which are direct replacements for the equivalent Am54LS/74LS MSI functions.

INCREASED FUNCTIONAL COMPLEXITY

As devices are operating at lower current levels, smaller area geometries can be employed. Thus, an LS design can often be produced on a smaller die than the equivalent standard TTL function. Further, the recent development of composite and self-aligning masking techniques allows even further reductions in device geometry sizes. These in turn result in faster speeds and the ability to manufacture more complex die.

Lower power dissipation also allows considerably more components to be incorporated onto a single chip without exceeding the recommended chip operating temperature.

The ability to produce large die at economical prices has improved the functional capability and variety of elements available in the LS family compared to standard TTL. Thus, LS technology is being used to implement many high-performance LSI functions in memory, interface and microprocessor, as well as logic families.

An important feature of all LS families is the new 20-pin Dual In-Line Package. This configuration fills the need for a package having the number of terminals necessary to accommodate the more complex products possible with LS, without the physical and cost disadvantages of the older 24-pin outline.

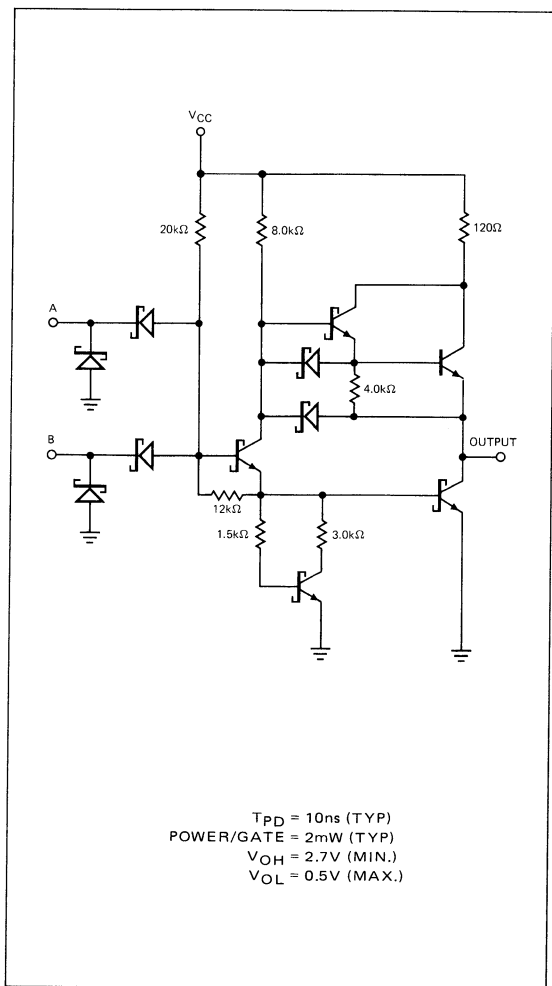


Figure 5. Low-Power Schottky "74LS" TTL Gate.

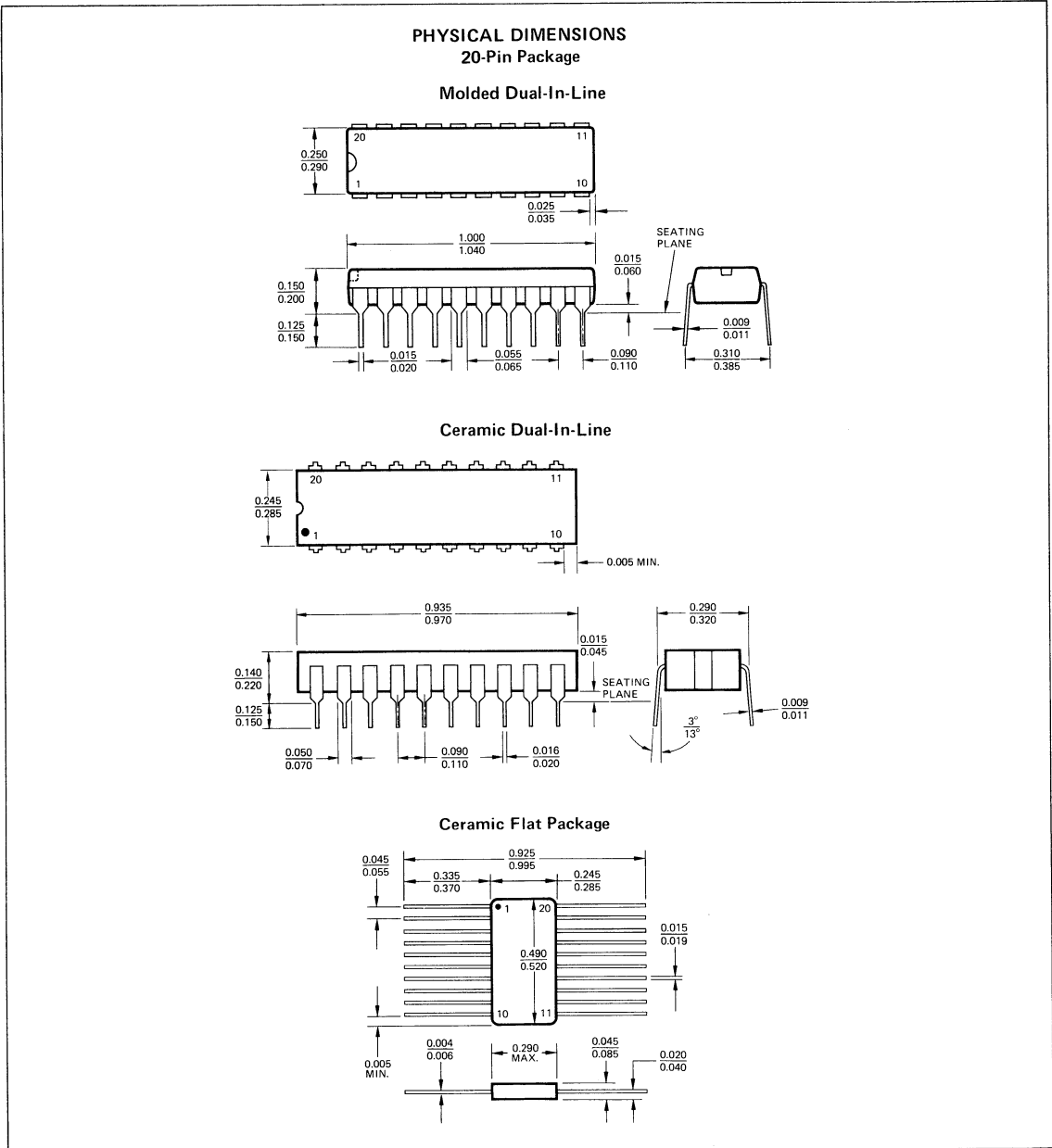
The 20-pin DIP has the same 300-mil center to center spacing between rows of pins as the popular 16-pin package. It therefore occupies about one third the board space of the 24-pin DIP with only a minor trade-off in functional capability. For both user and manufacturer this package is also considerably easier and lower cost to handle and test.

The 20-pin DIP is supplied in molded epoxy and hermetic ceramic versions. An hermetic ceramic flat pack is also available for military temperature range devices.

Functionally the 20-pin configuration is optimum for building octal functions. Eight input lines, eight output lines, power

supply and ground, leaves two pins available for control signals. Eight-bit devices are ideal for interfacing with popular eight-bit fixed instruction set MOS microprocessors. They are also useful in micro-programmable machines using bit slice processors implemented in multiples of eight-bits. An octal register device in a 20-pin package can reduce count by 50% over the two quad, or even more wasteful, two hex elements frequently used today.

A significant proportion of new Advanced Micro Devices' LS products introduced recently are in the 20-pin package.



2. D.C. Circuit Characteristics

CIRCUIT CONFIGURATIONS

The basic circuit design configuration of a Low-Power Schottky gate is similar to that of the original standard TTL elements. However, certain refinements have been made to optimize device performance when fabricated with the LS process.

In order to analyze the circuit configuration, Table 1 shows terms used in describing Advanced Micro Devices' LS circuits:

TABLE 1
D.C. CIRCUIT PARAMETER DEFINITIONS

- I_{IL} The current out of an input at a specified LOW voltage.
- I_{IH} The current into an input at a specified HIGH voltage.
- I_{OL} The current into an output when in the LOW state.
- I_{OH} The current out of an output when in the HIGH state (pull-up circuit only).
- I_{SC} The current out of an output in the HIGH state when shorted to ground. (Also called I_{QS})
- V_{CC} The range of supply voltage over which the device is guaranteed to operate.
- V_{IL} The guaranteed maximum input voltage that will be recognized by the device as a logic LOW.
- V_{IH} The guaranteed minimum input voltage that will be recognized by the device as a logic HIGH.
- V_{OL} The maximum guaranteed logic LOW voltage at the output terminal while sinking the specified load current I_{OL} .
- V_{OH} The minimum guaranteed logic HIGH voltage at the output terminal when sourcing the specified source current I_{OH} .

Both the input and output structures of the LS devices themselves have evolved through a number of configurations as designers have attempted to optimize circuit performance.

Depending on the function of the device any one of four commonly used inputs may be employed. The significant characteristics of each of these configurations are summarized in Figure 6.

The first LS designs used the familiar multi-emitter TTL input of Figure 6a. However because of low breakdown voltage and slow speed it is now used only where the geometry offers a significant advantage in circuit mask layout.

The second and still most widely used structure is the simple DTL style input of Figure 6b. This is the fastest version and it has good input breakdown voltage. In output functions having only a single gate delay between input and output, such as a three-state enable input, the low threshold of the DTL configuration causes the output node to be at a sufficiently low voltage to risk leakage problems at high temperature. The input of Figure 6c raises the threshold by one diode to overcome this problem (Figure 7). However because it is slower and uses more silicon area, its use is limited to special situations. A PNP input, Figure 6d, insures low d.c. loading for devices with common input/output pins such as the Am25LS23. However it is slow and has low breakdown voltage, comparable to the multi-emitter TTL structure.

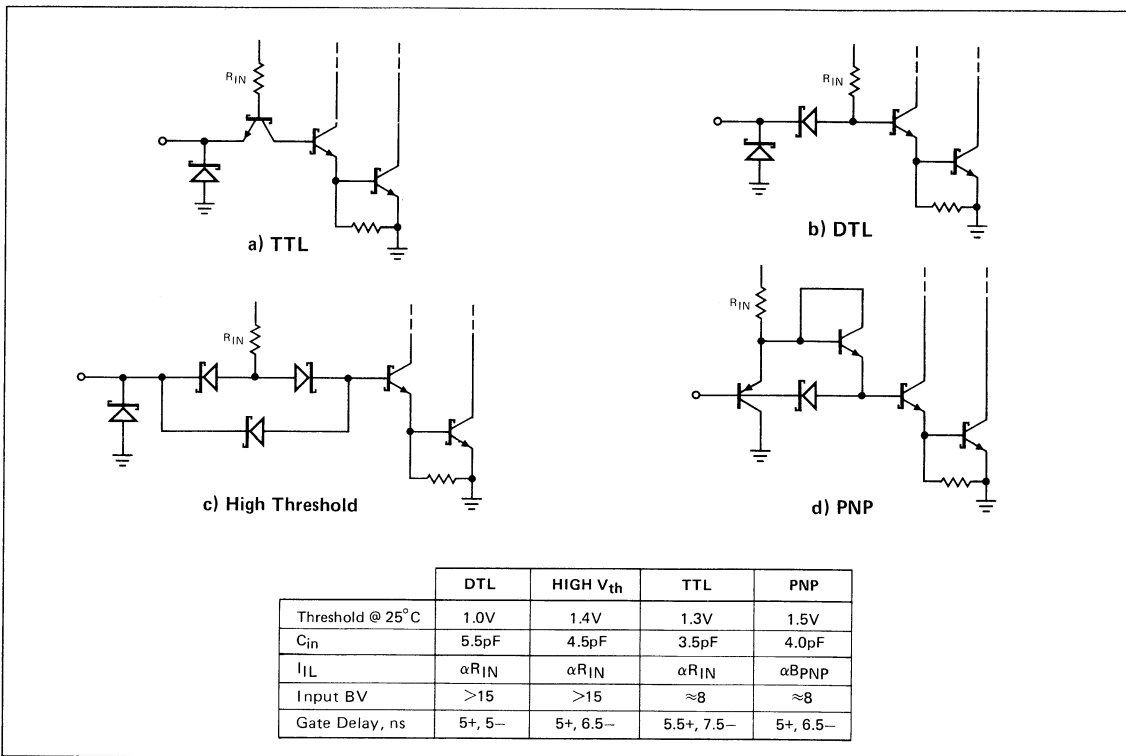


Figure 6. Low-Power Schottky Input Configurations.

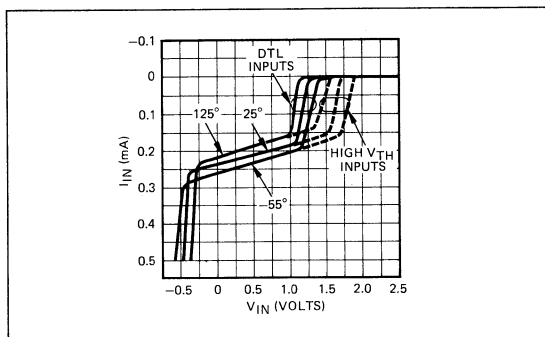


Figure 7. LS Input Characteristics for DTL and High Threshold Inputs.

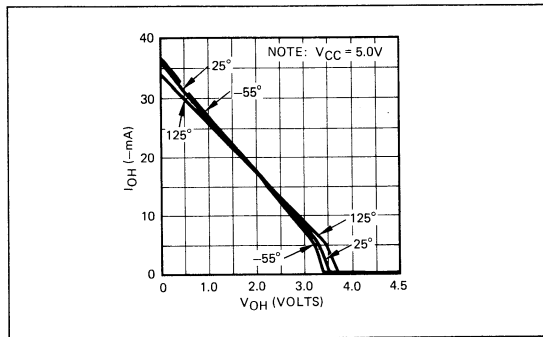


Figure 9. Typical V_{OH} Versus I_{OH} for Low-Power Schottky.

Figure 8 compares the early LS output configuration with the design most frequently used today. The change was made to provide clamping of positive ringing and to allow the higher I_{SC} currents now specified (see section 3). The typical V_{OH} versus I_{OH} curves of Figure 9 are similar for both versions.

This example displays an I_{SC} of approximately 35mA. Note that both of these designs include the "squaring" network (R_3 , R_4 and Q_5) at the base of the output pulldown transistor, Q_4 , which was not included on standard TTL families. The result of this is a sharp transition of V_{OUT} with V_{IIN} shown in Figure 10 for a simple gate function.

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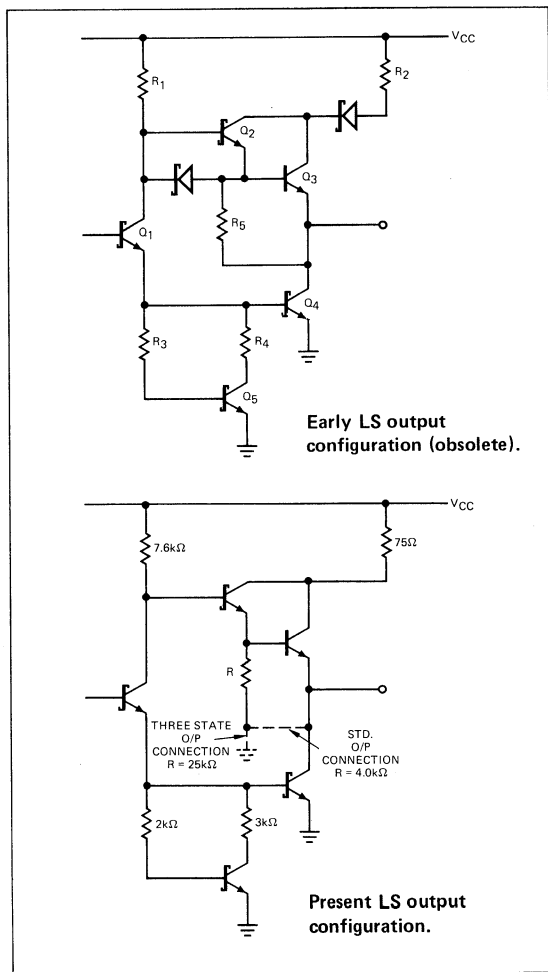


Figure 8. Low-Power Schottky Output Configurations.

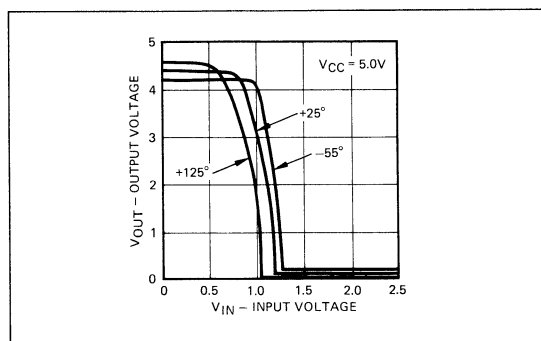


Figure 10. Typical Output Versus Input Voltage Characteristic.

The typical V_{OL} versus I_{OL} output characteristics of LS devices are shown in Figure 11. Most 74LS functions are specified at $V_{OL} = 0.4V$ at $I_{OL} = 4mA$ and $0.5V$ at $8mA$. Am25LS are specified at $0.45V$ for $I_{OL} = 8mA$. Some newer designs are being guaranteed at I_{OL} of $12mA$ and $24mA$. This curve indicates that lack of β at low temperature will not permit existing designs to be guaranteed to these higher values without severe yield loss.

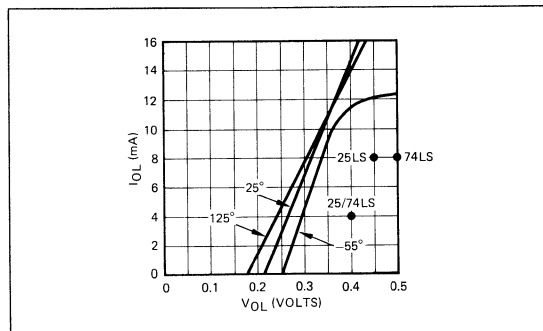


Figure 11. Typical LS V_{OL} Versus I_{OL} Characteristics.

TABLE 2
COMPARISON OF TTL DC PARAMETERS

Parameters	54LS/74LS LOW-POWER SCHOTTKY				25LS LOW-POWER SCHOTTKY				Units
	Conditions	Min.	Typ.	Max.	Conditions	Min.	Typ.	Max.	
V _{OL}	I _{OL} = 4.0mA			0.4	I _{OL} = 4.0mA			0.4	V
	I _{OL} = 8.0mA (COM'L Only)			0.5	I _{OL} = 8.0mA (MIL, COM'L)			0.45	
V _{OH}	I _{OH} = -400μA	MIL	2.5	3.4	I _{OH} = -440μA	MIL	2.5	3.4	V
		COM'L	2.7	3.4		COM'L	2.7	3.4	
V _{IL}	Logic LOW	MIL		0.7	Logic LOW	MIL		0.7	V
		COM'L		0.8		COM'L		0.8	
V _{IH}	Logic HIGH	2.0			Logic HIGH	2.0			V
I _{IL}	V _{IN} = 0.4V			-0.36	V _{IN} = 0.4V			-0.36	mA
I _{IH}	V _{IN} = 2.7V			20	V _{IN} = 2.7V			20	μA

Parameter	54S/74S AND 25S SCHOTTKY TTL				STANDARD TTL				Units
	Condition	Min.	Typ.	Max.	Condition	Min.	Typ.	Max.	
V _{OL}	I _{OL} = 20mA		0.3	0.5	I _{OL} = 16mA		0.2	0.4	Volts
V _{OH}	I _{OH} = -1.0mA	MIL	2.5	3.4	I _{OH} = -300μA	2.4	3.4		Volts
		COM'L	2.7	3.4					
V _{IL}	Logic LOW			0.8	Logic LOW			0.8	Volts
V _{IH}	Logic HIGH	2.0			Logic HIGH	2.0			Volts
I _{IL}	V _{IN} = 0.5V			-2.0	V _{IN} = 0.4V			-1.6	mA
I _{IH}	V _{IN} = 2.7V			50	V _{IN} = 2.4V			40	μA

INPUT/OUTPUT LEVELS

The input thresholds and output logic levels of LS circuits have been designed as far as possible to be compatible with those of standard TTL. Table 2 shows the guaranteed d.c. parameters of the Am54/74LS and second generation Am25LS families. Input current requirements (I_{IH}, I_{IL}) and therefore output drive needs (I_{OH}, I_{OL}) are significantly reduced over standard TTL.

A one unit load input current at logic HIGH, I_{IH}, for Am54LS/74LS is 20μA, compared with 40μA for Am54/74 standard TTL. Similarly at logic LOW, I_{IL} is reduced to -0.36mA from -1.6mA.

Corresponding reductions in the output drive requirements are I_{OL} = 4mA vs. 16mA at V_{OL} = 0.4V and I_{OH} = -400μA compared to 800μA.

FAN-OUT CAPABILITY

The fan-out capability of a logic family indicates the number of inputs which can be driven by a single output. It is defined as the maximum output drive current divided by the input current available.

Logic HIGH Fan-out = I_{OH}/I_{IH}

Logic LOW fan-out = I_{OL}/I_{IL}

Table 3 shows the fan-out capabilities of typical functions from the three families. The lower current operating levels of LS devices allow them to be specified at a logic LOW fan-out over the commercial range of more than twice that of standard TTL (22 vs. 10). The Am25LS family allows this advantage to be extended to the military range.

D.C. NOISE MARGIN

The D.C. noise margins of a digital system are defined from Figure 12 as follows:

Logic HIGH Noise Margin = V_{OH1} - V_{IH2}

Logic LOW Noise Margin = V_{IL2} - V_{OL1}

These parameters for LS devices are shown in Table 2. LS has a minimum logic HIGH output voltage of V_{OH} = 2.5V for military and 2.7V for the commercial temperature range. For standard TTL, V_{OH} is 2.4V. V_{IH} is 2.0V for both families.

Table 3 compares the guaranteed noise margin values for the standard TTL and LS devices. LS devices offer improved margin over standard TTL in the logic HIGH state, which is the most critical with regard to noise generation. At a similar fan-out, 10 for standard TTL and 11 for LS, noise margins in the LOW state are the same over the commercial range.

TABLE 3
FAN-OUT AND NOISE MARGIN
COMPARISON OF TTL AND LS FAMILIES.

a) LOGIC "HIGH" STATE

FAMILY	INPUT CURRENT I_{IH}	OUTPUT CURRENT I_{OH}	FAN-OUT		NOISE MARGIN	
			MILITARY	COMMERCIAL	MILITARY	COMMERCIAL
54/74	40 μ A	-800 μ A	20	20	400mV	400mV
54LS/74LS	20 μ A	-400 μ A	20	20	500mV	700mV
25LS	20 μ A	-440 μ A	22	22	500mV	700mV

b) LOGIC "LOW" STATE

FAMILY	INPUT CURRENT I_{IL}	OUTPUT CURRENT I_{OL}	FAN-OUT		NOISE MARGIN	
			MILITARY	COMMERCIAL	MILITARY	COMMERCIAL
54/74	-1.6mA	16mA	10	10	400mV	400mV
54LS/74LS	-0.36mA	4mA	11	11	300mV	400mV
		8mA	No Spec.	22	No Spec.	300mV
25LS	-0.36mA	4mA	11	11	300mV	400mV
		8mA	22	22	250mV	350mV

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Military LS devices have a 100mV lower noise margin in the LOW state than standard TTL. In most systems, this does not present a problem as the lower power supply currents being switched with LS generally result in lower system noise generation.

The logic levels guaranteed over the operating temperature ranges are of course worst case. Figures 13 and 14 show the typical values to be considerably better than these.

Am25LS D.C. FEATURES

The D.C. advantages offered by second generation Am25LS over 54/74LS devices can be seen from Table 3 as:

1. In the logic LOW state at a fan-out of 22 (8mA), Am25LS has 50mV greater noise margin (350mV vs. 300mV).
2. Am25LS products are guaranteed at a fan-out of 22 (8mA) over the military range. Am54LS is specified at fan-out of 10 (4mA) only.
3. Am25LS offers a symmetrical fan-out of 22 in both logic HIGH and logic LOW states, allowing full use of the logic LOW drive capability.

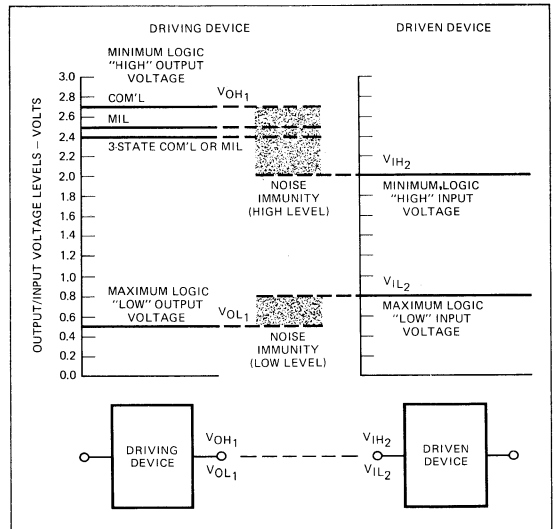


Figure 12. Input/Output Voltage Interface Conditions.

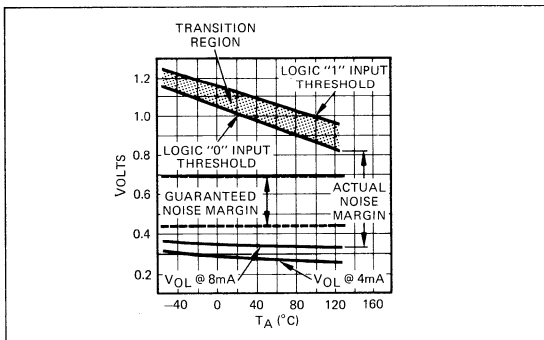


Figure 13. LS Logic "0" Noise Margin.

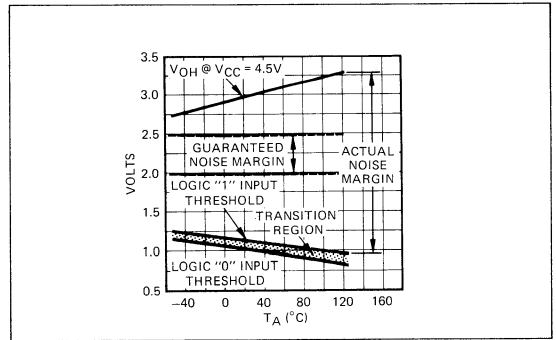


Figure 14. LS Logic "1" Noise Margin.

3. A.C. Characteristics

INTRODUCTION

Many Low-Power Schottky functions have been designed specifically to replace standard TTL elements in existing system designs. Their A.C. performance characteristics usually meet or exceed the limits of the earlier devices. The switching terms which are used on data sheets to describe the A.C. performance of these designs are summarized in Table 4. The more important parameters are discussed in detail in this section.

**TABLE 4
DEFINITION OF SWITCHING TERMS**

(All switching times are measured at the 1.3V logic level unless otherwise noted.)

- f_{MAX}** The highest operating clock frequency.
- t_{PLH}** The propagation delay time from an input change to an output LOW-to-HIGH transition.
- t_{PHL}** The propagation delay time from an input change to an output HIGH-to-LOW transition.
- t_{PW}** Pulse width. The time between the leading and trailing edges of a pulse, measured at the 50% points.
- t_r** Rise time. The time required for a signal to change from 10% to 90% of its measured values.
- t_f** Fall time. The time required for a signal to change from 90% to 10% of its measured values.
- t_s** Set-up time. The time interval for which a signal must be applied and maintained at one input terminal before an active transition occurs at another input terminal.
- t_h** Hold time. The time interval for which a signal must be retained at one input after an active transition occurs at another input terminal.
- t_R** Release time. The time interval for which a signal may be indeterminant at one input terminal before an active transition occurs at another input terminal. (The release time falls within the set-up time interval and is specified by some manufacturers as a negative hold time).
- t_{HZ}** HIGH to disable. The delay time from a control input change to the three-state output HIGH-level to high-impedance transition (measured at 0.5V change).
- t_{PHZ}** LOW to disable. The delay time from a control input change to the three-state output LOW-level to high-impedance transition (measured at 0.5V change).
- t_{ZH}** Enable HIGH. The delay time from a control input change to the three-state output high-impedance to HIGH-level transition.
- t_{PZH}** Enable LOW. The delay time from a control input change to the three-state output high-impedance to LOW-level transition.

PROPAGATION DELAYS

The standard designations for delays through combinatorial logic networks are t_{PHL} and t_{PLH}. A delay from an input change to an output going LOW is called t_{PHL}, while t_{PLH} is the delay from an input change to an output going HIGH.

Figure 15 shows a typical waveform with the output changing during the interval indicated by the diagonal, sloping line. Note that all switching times shown are measured at the 1.3 volt logic level.

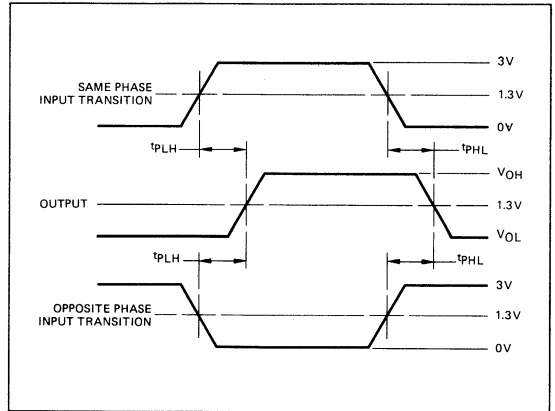


Figure 15. Propagation Delay.

Typical values for a single gate propagation delay t_{PHL} in Low-Power Schottky functions are 8–10ns into a 15pF load. Higher performance LS families, such as Am25LS, exhibit delays in the 4 – 6ns range. These propagation delays will increase by 2 – 4ns at an output loading of 50pF or approximately 0.1ns per pF. See Figure 16.

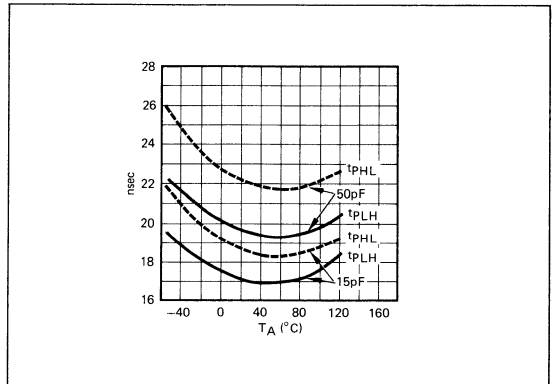


Figure 16. Am25LS138 Typical Propagation Delays Address to Output (3 Levels).

Table 5 shows the worst case delays through typical two and three deep gate MSI functions such as multiplexers and decoders. Speed improvements attainable with the Am25LS higher performance LS devices at this level of complexity are shown to be in the range of 20 to 40%. Guaranteed delays into 50pF loads are being specified on all new Am25LS data sheets. See Table 8.

TABLE 5
COMPARISON OF AC PARAMETERS ($T_A = +25^\circ\text{C}$)

LS138 3-Line to 8-Line Decoder/Demultiplexer

Am25LS138

Am54LS138
Am74LS138

Parameters	Description	Test Conditions	Min.	Max.	Min.	Max.	Units
t_{PLH}	Two Level Delay	$V_{CC} = 5.0\text{V}, R_L = 2\text{k}\Omega, C_L = 15\text{pF}$		15		20	ns
t_{PHL}	Select to Output			21		41	
t_{PLH}	Three Level Delay			23		27	ns
t_{PHL}	Select to Output			27		39	
t_{PLH}	G2A or G2B to Output			15		18	ns
t_{PHL}				23		32	
t_{PLH}	G1 to Output			18		26	ns
t_{PHL}				27		38	

LS158 Quadruple 2-Line to 1-Line Data Selectors/Multiplexers

Am25LS158

Am54LS158
Am74LS158

Parameters	Description	Test Conditions	Min.	Max.	Min.	Max.	Units
t_{PLH}	Data to Output	$V_{CC} = 5.0\text{V}, R_L = 2\text{k}\Omega, C_L = 15\text{pF}$		9		12	ns
t_{PHL}				11		12	
t_{PLH}	Strobe to Output			12		17	ns
t_{PHL}				17		18	
t_{PLH}	Select to Output			20		20	ns
t_{PHL}				21		24	

2

EDGE RATES

The rise and fall times of Low-Power Schottky devices are similar to those of standard TTL. Into a 50pF load fall time, t_f , is typically 6-8ns, while rise time, t_r , is in the 9-12ns range. A.C. parameters are measured at $t_f \leq 6\text{ns}$ and $t_r \leq 15\text{ns}$.

As with standard TTL, careful P.C. board layout rules should be employed to avoid problems which can occur at these relatively fast edge rates. In particular, precautions should be taken to insure that transmission line effects do not cause false switching or ringing and oscillation problems on lines longer than 18 inches. See Section 4 for more information.

SEQUENTIAL DEVICES

Set-up time, t_s , hold time, t_h , and release time, t_R , are the most important parameters for specifying sequential elements such as latches, flip-flops and registers.

For these synchronous devices, inputs must be stable for a certain period of time before the clock or enable pulse. This interval is the region in time during which devices are "sampling" their inputs. As an example, consider a latch with a D input and an active LOW clock. The latch will store the information present on its input just before the clock goes HIGH. The question is, how long does the input level have to be present and stable before the clock goes HIGH? A particular device will "sample" its input at some exact instant, but in a group of devices some are slower than others. The result is an interval of some time called set-up time during which all devices, fast or slow, will "sample" their inputs.

All devices exhibit a hold time. That is a period of time after the clock or enable pulse transition during which the data cannot be changed without loss of input intelligence. This hold time occurs after the clock goes HIGH. Figure 17 shows the input requirements and definitions for data entry. Release time is negative hold time or the time period prior to the clock input after which the data can be released. Typical examples of LS characteristics and the improvements attainable with high performance Am25LS sequential devices are shown in Table 6.

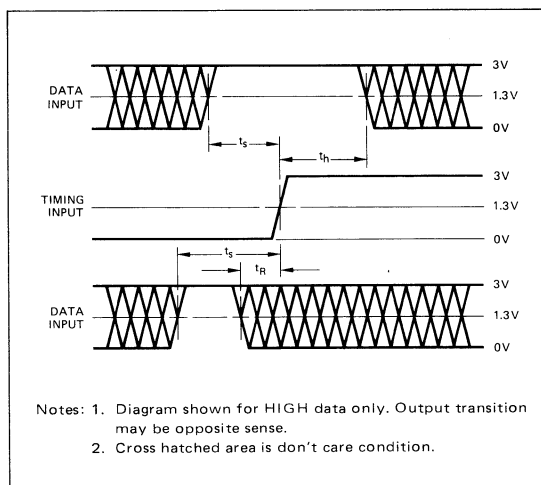


Figure 17. Set-up, Hold, and Release Time Definitions.

f_{MAX} .

A frequently misunderstood parameter on data sheets is maximum clock frequency f_{MAX} . This was defined by the early TTL manufacturers as the maximum toggle frequency which can be attained by the device under ideal conditions with no constraints on t_r , t_f , pulse width, or duty cycle. Although f_{MAX} as specified cannot usually be attained in an operating system, it is a relatively easy parameter to test and provides a convenient measure of comparative performance between different devices. For instance, Table 6 shows the Am54/74LS174 at $f_{MAX} = 30\text{MHz}$ (min.) while the high-performance Am25LS is specified at 40MHz (min.). Actual toggle frequency in a system must be determined from the specific signal conditions presented to the device.

TABLE 6
SWITCHING CHARACTERISTICS ($T_A = 25^\circ\text{C}$)

Parameters	Description	Test Conditions	Am25LS174 Am25LS175		Am54LS174 Am74LS174 Am74LS175		Units
			Min.	Max.	Min.	Max.	
t_{PLH}	Clock to Output	$V_{CC} = 5.0V, R_L = 2k\Omega, C_L = 15pF$		23		30	ns
t_{PHL}				22		35	
t_{PLH}	Clear to \bar{Q} Output, LS175 only				25		ns
t_{PHL}					35		
t_{pw}	Pulse Width		Clock	17		20	ns
			Clear	20		20	
t_s	Data Set-up Time			20		20	ns
t_s	Set-up Time Clear Recovery (in-active) to Clock			20		25	ns
t_h	Data Hold Time			5		5	ns
$f_{MAX.}$	Maximum Clock Frequency			40		30	MHz

EFFECTS OF TEMPERATURE AND POWER SUPPLY VARIATIONS

Standard TTL devices exhibit severe degradation in A.C. performance towards the recommended limits of the operating temperature and power supply voltage ranges.

At elevated temperature and/or high V_{CC} levels, charge storage begins to slow down A.C. response. At the other extreme, low temperature and/or low V_{CC} , the loss of β causes a similar problem. These combined effects can cause more than 50% degradation in performance over the full military temperature and power supply extremes.

As noted in Section 1, Low-Power Schottky technology reduces the impact of both of these effects on performance. β degradation at cold temperatures is far less severe and Schottky clamping largely eliminates the effects of charge storage at high temperature.

General guidelines for variation in the AC response over temperature and power supply variations are not easy to specify. Typical measured variations for a combinatorial and a sequential device are shown in Figures 16 and 18.

The system's designer would like a factor which will allow his system to meet specification with minimum design overkill. However, the component engineer often requires maximum delays to be guaranteed. For system design guidelines, the AC derating factors of Table 7 may be useful.

It must be emphasized that the values of Table 7 are typical. However as it is unlikely that any given system will contain all worst case devices they will usually yield a fairly safe prediction of the system performance which can be achieved.

Individual components will of course be slower than these typical numbers. These must be reflected on procurement specifications. A general rule of thumb would be to double the system design guidelines of Table 7. New Am25LS specifications are now being published with worst case parameters guaranteed over the operating power supply and temperature ranges, as well as at a realistic system load condition of 50pF. A typical example of this format is shown in Table 8.

SHORT CIRCUIT OUTPUT CURRENT

To improve performance, in 1975 TI lowered the short-circuit current limiting resistor value. This increased the I_{SC} (I_{OS}) range from -6 to $-42mA$ up to -30 to $-130mA$. The overall

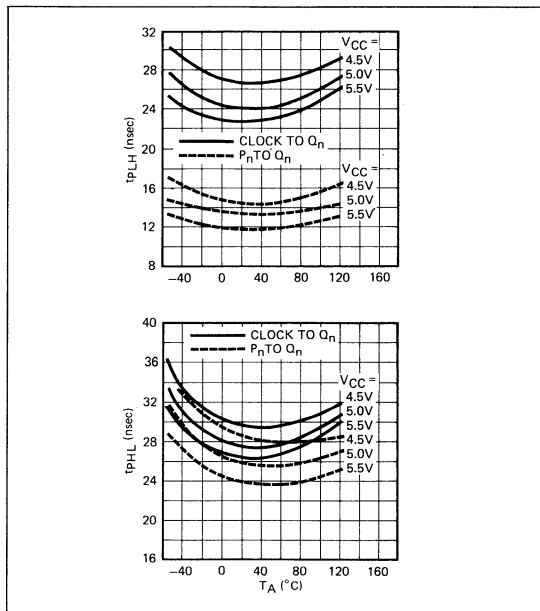


Figure 18. Typical A.C. Variations with Temperature and Power Supply for Am25LS193 Counter.

TABLE 7
GUIDELINES FOR TYPICAL VARIATION OF A.C. PARAMETERS WITH COMBINED TEMPERATURE AND V_{CC} VARIATION

Temperature Range	V_{CC} Variation (Nominal 5V)	AC Derating Factor	
		System	Component
COM'L, 0°C to $+70^\circ\text{C}$	None	5%	10%
COM'L, 0°C to $+70^\circ\text{C}$	$\pm 0.25V$	15%	30%
MIL, -55°C to $+125^\circ\text{C}$	None	15%	30%
MIL, -55°C to $+125^\circ\text{C}$	$\pm 0.5V$	25%	50%

delay when driving very large capacitive loads (>150pF) was reduced somewhat as a result. However, the inherent circuit performance still dominates in normal applications such that the Am25LS and other high performance families remain faster even when driving large capacitive loads.

As an attempt to offer standardized specifications, most manufacturers, including Advanced Micro Devices, Fairchild, Motorola, Raytheon, and Signetics, also lowered their short-circuit current limiting resistor values on new designs to provide a typical I_{SC} of -60mA. Most manufacturers now specify -15 to -100mA to accommodate both old and new circuits. The maximum value of -100mA was chosen, as -130mA was felt to be too high for a noise sensitive system design. The Am25LS high performance family is specified even tighter, with the maximum I_{SC} limited to -85mA.

Early in 1977 TI changed their data sheets yet again to specify I_{SC} from -20mA to -100mA on regular outputs and -30mA to -130mA on three-state outputs.

TABLE 8
Am25LS2513 THREE-STATE PRIORITY ENCODER
A.C. SPECIFICATION FORMAT FOR V_{CC} AND TEMPERATURE
EXTREMES AND 50pF LOAD CONDITION

SWITCHING CHARACTERISTICS

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units	
t _{PLH}	T _i to An (In-phase)	C _L = 15pF R _L = 2.0kΩ		17	25	ns	
t _{PHL}				17	25		
t _{PLH}	T _i to An (Out-phase)			11	17	ns	
t _{PHL}				12	18		
t _{PLH}	T _i to E _O			7.0	11	ns	
t _{PHL}				24	36		
t _{PLH}	E _I to E _O			11	17	ns	
t _{PHL}				23	34		
t _{PLH}	E _I to An			12	18	ns	
t _{PHL}				14	21		
t _{ZH}	G ₁ or G ₂ to An			23	40	ns	
t _{ZL}				20	37		
t _{ZH}	G ₃ , G ₄ , G ₅ to An			20	30	ns	
t _{ZL}				18	27		
t _{HZ}	G ₁ or G ₂ to An		C _L = 5.0pF R _L = 2.0kΩ		17	27	ns
t _{LZ}					19	28	
t _{HZ}	G ₃ , G ₄ , G ₅ to An			16	24	ns	
t _{LZ}				18	27		

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SWITCHING CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions	Am25LS COM'L		Am25LS MIL		Units	
			T _A = 0°C to +70°C V _{CC} = 5.0V ±5%		T _A = -55°C to +125°C V _{CC} = 5.0V ±10%			
			Min.	Max.	Min.	Max.		
t _{PLH}	T _i to An (In-phase)	C _L = 50pF R _L = 2.0kΩ		31		37	ns	
t _{PHL}				30		34		
t _{PLH}	T _i to An (Out-phase)			22		27	ns	
t _{PHL}				22		25		
t _{PLH}	T _i to E _O			15		18	ns	
t _{PHL}				48		60		
t _{PLH}	E _I to E _O			19		21	ns	
t _{PHL}				46		57		
t _{PLH}	E _I to An			22		25	ns	
t _{PHL}				27		32		
t _{ZH}	G ₁ or G ₂ to An			42		49	ns	
t _{ZL}				43		49		
t _{ZH}	G ₃ , G ₄ , G ₅ to An			36		43	ns	
t _{ZL}				35		43		
t _{HZ}	G ₁ or G ₂ to An		C _L = 5.0pF R _L = 2.0kΩ		34		40	ns
t _{LZ}					34		40	
t _{HZ}	G ₃ , G ₄ , G ₅ to An			30		35	ns	
t _{LZ}				31		35		

4. Design Guidelines

POWER SUPPLY CONSIDERATIONS

The recommended power supply voltage (V_{CC}) for all TTL circuits, including LS, is +5V. Commercial temperature range devices, designated 74LS or in the case of Am25LS with the suffix C, are specified with a $\pm 5\%$ supply tolerance ($\pm 250\text{mV}$) over the ambient range 0°C to 70°C . Military range parts, designated 54LS or in the case of Am25LS with the suffix M, are guaranteed with a $\pm 10\%$ supply tolerance ($\pm 500\text{mV}$) over an ambient temperature range of -55°C to $+125^\circ\text{C}$. The power supply should be well regulated with a ripple less than 5% and with regulation better than 5%. Even though LS devices generate significantly smaller power supply spikes when switching than standard TTL, on-board regulation is still preferable to isolate this noise to one board.

A low-inductance transmission line power distribution bus with good RF decoupling is necessary for large systems. On all boards, ceramic decoupling capacitors of $0.01\mu\text{F}$ to $0.1\mu\text{F}$ should be used at least one for every five packages, and one for every one-shot (monostable), line driver and line receiver package. In addition, a larger tantalum capacitor of $20\mu\text{F}$ to $100\mu\text{F}$ should be included on each card. On boards containing a large number of packages, a low impedance ground system is essential. The ground can either be a bus or a ground which is incorporated with the V_{CC} supply to form a transmission line power system. Separate power transmission systems can be attached to the board to provide this same feature without the cost of a multi-layer PC card.

UNUSED INPUTS

An unused input to an AND or NAND gate should not be left floating as it can act as an antenna for noise. On devices with storage, such as latches, registers and counters, it is particularly important to terminate unused inputs (MR, PE, PL, CP) properly since a noise spike on these inputs might change the contents of the memory. This technique optimizes switching speed as the distributed capacitance associated with the floating input, bond wire and package leads is eliminated. To terminate, the input should be held between 2.4V and the maximum input voltage. One method of achieving this is to connect the unused input to V_{CC} . Most LS inputs have a breakdown voltage $>7\text{V}$ and require no series resistor. Devices specified with a maximum 5.5 volt breakdown should use a $1\text{k}\Omega$ to $10\text{k}\Omega$ current limiting series resistor to protect against V_{CC} transients. Another method is to connect the unused input to the output of an unused gate that is forced HIGH. Do not connect an unused input to another input of the same NAND or AND function. Although recommended for standard TTL, with LS this increases the input coupling capacitance and reduces A.C. noise immunity.

TRANSMISSION LINE EFFECTS

The relatively fast rise and fall times of Low-Power Schottky TTL (5 to 15ns) can cause transmission line effects with interconnections as short as 18 inches. With one TTL device driving another and the driver switching from LOW to HIGH, if the propagation delay of the interconnection is long compared to the signal rise time, the arrangement can behave like a transmission line driven by a generator with a non-linear output.

The initial voltage step at the output, just after the driver has switched, propagates down the line and reflects at the end. In the typical case where the line is open ended or terminated in an impedance greater than its characteristics impedance (Z_{OL}), the reflected wave arrives back at the source and increases V_{OUT} . If the total round-trip delay is longer than the rise time of the driving signal, a staircase response results at the driver output and along the line. If one of the driven devices is connected close to the driver, the initial output voltage (V_{OUT}) seen by it might not exceed V_{IH} . The state of the input is undetermined until after the round trip of the transmission line, thus slowing down the response of the system.

The longest interconnection that should be used with LS devices without incurring problems due to line effects is in the 10–12 inch range.

With longer interconnections, transmission line techniques should be used for maximum speed. Good system operation can be obtained by designing around 100 ohm lines. A 0.026 inch (0.65mm) trace on a 0.062 inch epoxy-glass board ($E_r = 4.7$) with a ground plane on the other side represents a 100Ω line. 28 to 30 gauge wire (0.25 to 0.30mm) twisted pair line has a characteristic impedance of 100 to 115Ω .

LINE DRIVING AND RECEIVING

For lines longer than 2 feet, twisted pairs of coaxial cable should be used. The characteristic impedance or the transmission media should be approximately 120Ω such as twisted pairs of #26 wire or 100Ω coax. A possible choice is cables with a characteristic impedance R_0 of 100Ω such as ribbon cable or flat cable with controlled impedance. Resistive pull-ups at the receiving end can be used to increase noise margin. Where reflection effects are unacceptable, the line must be terminated in its characteristic impedance. A method shown in Figure 19

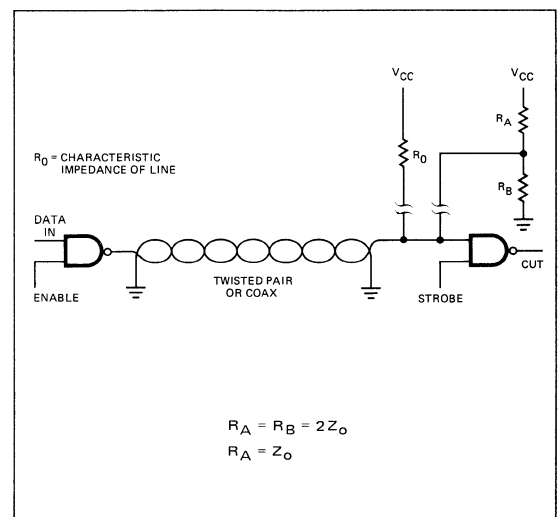


Figure 19. LS Driving Twisted Pair.

has the output of the line tied to V_{CC} through a resistor equivalent to the characteristic impedance of the line. As the output impedance of the LS driver is low and must sink the current through it, in addition to the current from the inputs being driven, a useful technique is to terminate the line in a voltage divider with two resistors, each twice the line impedance. This reduces the extra sink current by 50%. Where the line exceeds five feet in length it is preferable to dedicate gates solely to line driving.

For additional noise immunity when driving long lines, a differential line driver and line receiver may be used. These dedicated line interface circuits drive a twisted pair of wires differentially, permit easy termination of lines and provide excellent common mode noise rejection.

The Am26LS31 driver and Am26LS32 and Am26LS33 are quad differential line drivers and receivers satisfying the interface requirements of EIA RS-422 and 423 as well as military applications, Figure 20. They are designed to operate off the standard 5V power supplies of the LS logic devices. More applications information on line termination techniques is provided on the above mentioned device data sheets.

CROSS-TALK AND RINGING

These two problems may be experienced with all forms of high speed digital logic. Crosstalk is the coupling of energy from one circuit to another via real or parasitic capacitance and inductance. Ringing is the possible rebound of the signal into the

input threshold region (0.8 – 2.0V) following a HIGH-to-LOW level change. When a driver switches from a HIGH-to-LOW state the output voltage should fall below the threshold value. However, a line having a very low characteristic impedance does not allow transistor Q5 in the NAND gate example to saturate, and the resulting output voltage may not be low enough to switch an adjacent device until two or more line delay times. The low current levels at which LS devices operate, coupled with the low output impedance in both HIGH and LOW Logic states, minimize crosstalk effects. Input clamp diodes provided on all LS devices are extremely effective in reducing ringing phenomenon.

Care should be taken to insure that signals with falling edges faster than 2.5-3ns/volt are not coupled into the input of an LS function. Even though the signal may not pass into the threshold region, if the pulse edge is fast enough, sufficient energy may be capacitively coupled into a sequential device to cause it to change state: High speed Schottky elements in a test setup can exceed this limit. However in an active system, the edges will generally be slowed sufficiently to eliminate any problem.

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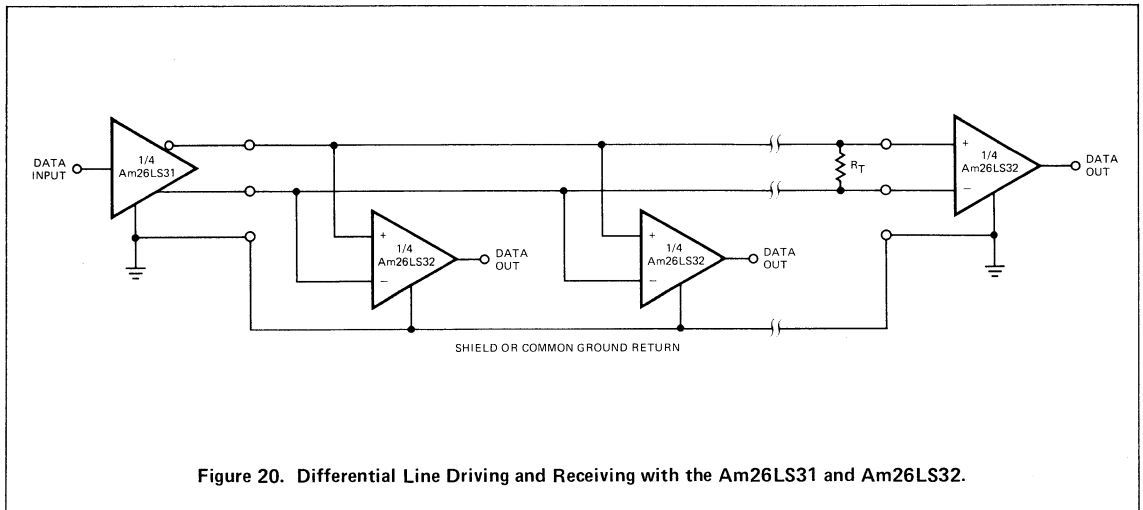


Figure 20. Differential Line Driving and Receiving with the Am26LS31 and Am26LS32.

RELIABILITY REPORT SCHOTTKY AND LOW-POWER SCHOTTKY TTL DEVICES

By Lawrence Drake and Jeff Kersey

RELIABILITY TESTING OF SCHOTTKY DEVICES

Reliability testing of AMD TTL devices using gold-doped and Schottky (S and LS) processes shows both technologies to be extremely stable. Life test data (MIL-STD-883, Method 1005 for Group C, subgroup 5 testing 1000 hours, 125°C Operating Life) for 3610 parts yielded two failures — one slightly out of specification at 25°C only, the other suspected to have been damaged by handling. Even considering the two failures, the failure rate is only 0.05% per thousand hours at 125°C or 0.0005% per thousand equivalent at 70°C (1 e v acceleration activation energy). Three lots (231 parts) were Schottky TTL devices.

The basic design reliability of Schottky technology has been demonstrated in an extended life test on special circuit patterns devised so that individual circuit elements could be measured. Two groups of 22 of these special test patterns were stressed as indicated in Table 1 at 125°C. Change in the parameters were recorded at 11,000 hours for Group I and 10,000 hours for Group II and are presented in Tables II and III. No device failures occurred during these tests and no significant drifts or trends are evident. Several leakage parameters (I_{IH} , I_{CEO} , I_{LK}) have high percentage changes but the absolute values are in the nanoamp range and approach the measurement systems resolution limit. Decreases as well as increases in these currents occurred so trends are not indicated.

Several devices (74LS174, 74LS175 and 25LS161) were checked for parameter drift during 1000 hour Life Tests at 125°C using a MIL-STD-883, Method 1005, Condition C (Steady-State, Power and Reverse Bias) circuit. As can be seen from Tables IV, V and VI, no significant change occurred; again no device failures in any of these tests. The tests for the 74LS174's and 74LS175 contained 4 reference or control units, not subjected to the test, but included in the pre and post-test measurements. In most instances the test parts parameter shift was within measurement spread for the control units.

Several Group C tests as previously mentioned have been run on Schottky devices. These tests as well as the ones previously discussed are presented in Table VII.

FAILURE MECHANISM OF TTL MSI/LSI CIRCUITS

Standard TTL circuits: AMD's experience as well as that of the Military as reported in RADCR Reports and other sources indicate that bond lead wire and package defects account for more than half of device failures. Diffusion and other bulk defect, oxide faults, metallization damage and other die fabrication anomalies cause 10 to 15% of failures. Surface problems contribute 20 to 40%. Die fabrication problems do cause some yield loss but are not time-stress dependent failure mechanisms. Thus assembly anomalies and surface effects are the usual life limiting items.

Schottky/LS Circuits: Schottky diodes made by a simple metal-semiconductor contact have a reverse characteristic that is predominantly edge leakage, Figure 1a. Most Schottky diodes have superimposed on them an annular diffused junction diode of a higher breakdown than that expected of the Schottky diode. This "guard ring" allows the Schottky diode to avalanche breakdown as expected by theory, Figure 1b. In addition non-guard ring Schottky diodes suffer degradation of the reverse leakage characteristics if biased into breakdown repeatedly; for this reason our devices are designed so that no user accessible non-guard ring Schottky diodes exist. Other than this anticipated potential problem corrected by design there appear to be no distinct Schottky failure mechanisms in non-aluminum contact Schottky devices.

SCHOTTKY PROCESSING DETAILS

Processing of Schottky devices is identical to that of TTL devices, with the exception of the gold doping steps, to the point where contact openings have been etched. Following the contact etch, platinum is sputtered to form a uniform deposition across the surface of the wafer. This is followed by a high-temperature sinter to form platinum silicide in each contact window. All unreacted platinum is stripped with an etchant not active on the platinum silicide. Platinum silicide remains in the contact windows and no photomasking was involved, just a selective etch.

The next step is the deposition of the titanium tungsten barrier material followed by the aluminum layer. Both layers are then etched to delineate the circuit intra-connect pattern using standard photomasking techniques.

The entire process seems complicated at first glance because of the three-layer structure that results, but each layer serves a definite purpose.

Platinum silicide forms the actual Schottky barrier junction and produces a reliable diode with stable and predictable characteristics. Platinum could conceivably be used as the current carrying intra-connect metallization but there is no platinum etch compatible with current photomasking materials.

Tungsten is required to prevent the diffusion of aluminum into the platinum silicide junction; however, tungsten alone has a tendency to peel because of poor adherence to the SiO₂. The addition of titanium solves the adhesion problem and the resulting composite material has etch characteristics similar to aluminum so that only one photomasking and etch operation is necessary to define the intra-connects, rather than separate operations for Ti-W and Al.

Surface passivation and scratch protection is applied and etched in exactly the same manner as those devices using aluminum metallization only.

Extensive life test data on this structure proves that it is a repeatable, stable, and reliable process.

COMMENTS

Data has been presented from an ongoing reliability program for Schottky devices. No device failures have occurred in nearly one-half million unit hours of life testing at 125°C. Current data from various sources indicate that $I_e v$ is a conservative value for activation energy in calculating acceleration factors.

Using this value and a Poisson distribution an equivalent 70°C failure rate of no worse than 0.001% per thousand hours is estimated at a 90% confidence.

Schottky and LS integrated circuits provide improved performance over standard gold-doped TTL devices at the same high reliability experienced with these non-Schottky parts.

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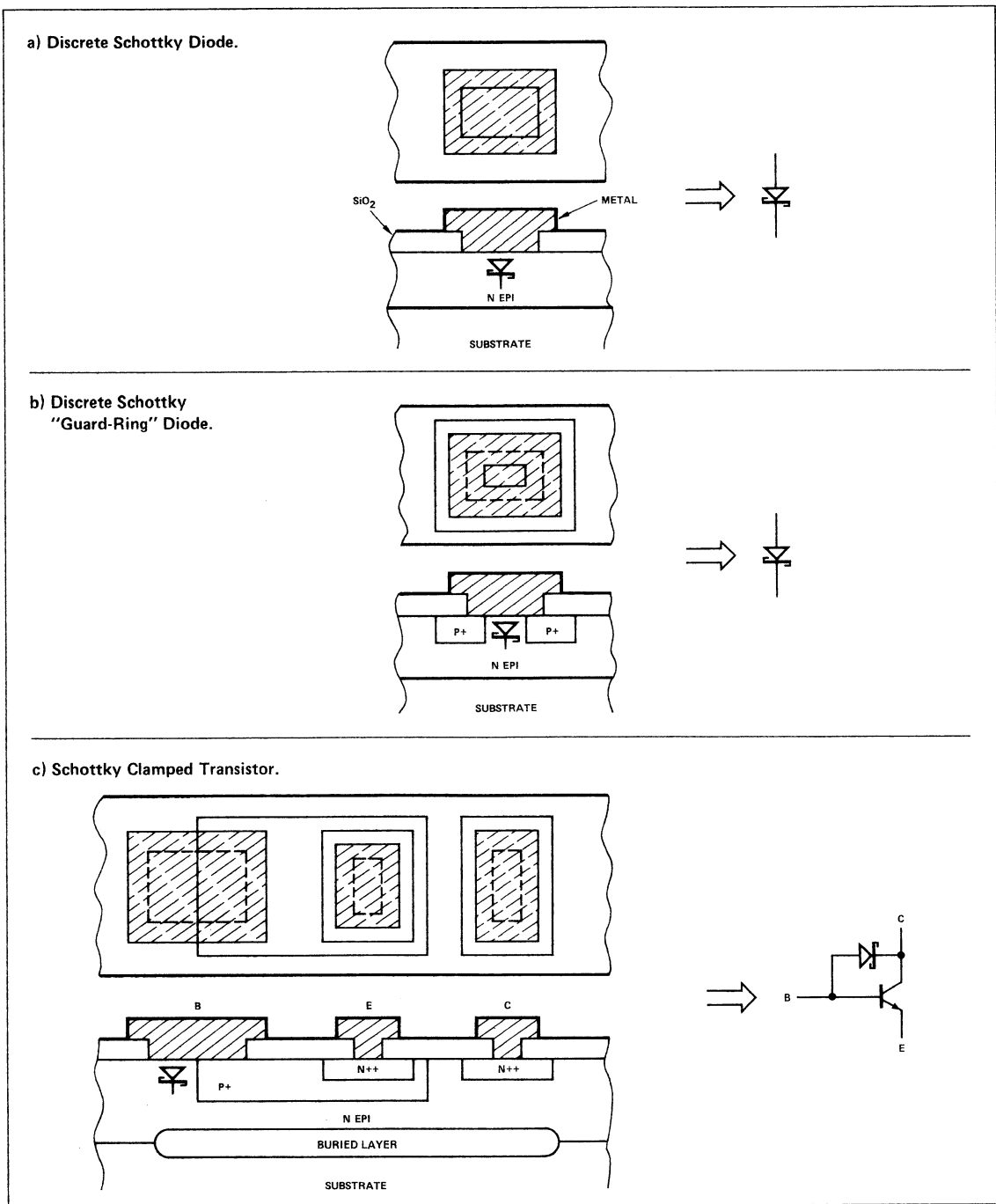


Figure 1. Schottky Device Construction.

**TABLE I
LIFE TEST BIAS CONDITIONS**

Standard Gate Schottky-clamped 2-input TTL NAND gate	Gate ON Output open $V_{CC} = 5.0V$
Phase-Splitter Geometry 1.0 mil emitter, non-guard ring Schottky clamp diode	$I_B = 1mA$ $I_C = 5mA$ Emitter = GND
Output Geometry 4.5 mil emitter, guard-ring Schottky clamp diode	$I_B = 4mA$ $I_C = 20mA$ Emitter = GND
Resistors 600 Ω base resistor in series with a 40 Ω emitter resistor.	$I_R = 7.8mA$
Schottky Diode 0.5 mil x 3.0 mil, non-guard ring structure	$I_D = 10mA$
Metallization Run 0.2 mil by approximately 60 mil	$I = 10mA$
Ambient Temperature	125°C

**TABLE II
TEST PATTERN GROUP I
11,000 HR DATA SUMMARY**

Structure	Parameter	Average Initial Value	Average Delta	% Average Delta
Standard Gate	V_{OS}	.179V	(-) 1.1mV	.61
	V_{OL}	.398V	(-) 8.3mV	2.1
	V_{OH}	2.954V	(+) 6.3mV	.21
	I_{IH}	.317 μA	(+) .34 μA	107.0
Phase- Splitter Geometry	V_{BC}	.626V	(+) 5.0mV	.8
	V_{BE}	.827V	(+) 1.4mV	.17
	V_{SAT}	.518V	(+) 1.7mV	.33
	h_{FE}	58.00	(-) 3.2	5.5
	I_{CEO}	.04 μA	.03 μA	83.0
Output Geometry	V_{BC}	.621V	(+) 2.1mV	.34
	V_{BE}	.848V	(+) 2.0mV	.24
	V_{SAT}	.345V	3.4mV	.99
	h_{FE}	66.00	(-) 1.3	1.97
	I_{CEO}	.025 μA	(-) .023 μA	92.0
Resistors	V	.527V	(+) 4.7mV	.89
Schottky Diode	$V_{SBD} @ 100\mu A$.398V	(+) 8.0V	2.0
	$V_{SBD} @ 10mA$.630V	(+) 3.0mV	.48
	I_{LK}	.08 μA	(-) .06 μA	79.0
	V_{BR}	24.5V	(+) 1.56V	6.4
Metal Run	V	117.0mV	(+)42mV	35.9

**TABLE III
TEST PATTERN GROUP II
10,000 HR DATA SUMMARY**

Structure	Parameter	Average Initial Value	Average Delta	% Average Delta
Standard Gate	V _{OS}	.249V	(+) 2.3mV	.92
	V _{OL}	.489V	1.7mV	.35
	V _{OH}	2.958V	3.6mV	.12
	I _{IH}	.114μA	(+) .09μA	81.0
Phase-Splitter Geometry	V _{BC}	.563V	(-) 2.0mV	.36
	V _{BE}	.841V	(+) 2.5mV	.3
	V _{SAT}	.718V	1.4mV	.19
	h _{FE}	28.4	.2	.7
Output Geometry	I _{CEO}	.298μA	(-) .3μA	101.0
	V _{BC}	.551V	(+) 4.5mV	.82
	V _{BE}	.849V	(+) 1.9mV	.22
	V _{SAT}	.432V	1.1mV	.25
Resistors	h _{FE}	62.0	.5	.8
	I _{CEO}	2.03μA	(-) .32μA	15.8
	V	.562V	(-) 2.4mV	.46
	Schottky Diode	√SBD @ 100μA	.328V	(+) 2.1mV
√SBD @ 10mA		.566V	(+) 3.0mV	.53
I _{LK}		.09μA	.09μV	100.0
V _{BR}		24.9V	97mV	.39
Metal Run	V	124.0mV	6.4mV	5.2

2

**TABLE IV
1000 HOUR LIFE TEST DATA
FOR Am25LS161**

Test No.	Parameter	Limit		Initial Value			Delta @ 1000 Hrs.			Units
		Min.	Max.	Min.	Typ.	Max.	Min.	Typ.	Max.	
101	Input Clamp Voltage		-1.5	-.822	-.839	-.921	-.019	-.027	-.113	Volts
141	Input LOW Current		-800	-493	-576	-656	+1.0	-1.0	-2.3	μA
143	Input HIGH Current @ 2.7V		40	0	0	0	0	0	0	μA
144	Input HIGH Current @ 7.0V		200	0	0	0.9	0	0	1.4	μA
200	Output HIGH Voltage	2.5		3.04	3.07	3.11	-.01	0	+.03	Volts
202	Output Short-Circuit Current	-15	-85	-32.0	-35.9	-42.5	-.8	-1.4	-4.2	mA
204	Output Leakage Current	-	-	0	0	1.0	0	0	-1.0	μA
205	Output LOW Voltage at I _{OL} = 3mA		0.4	.271	.295	.328	-.007	0	.005	Volts
206	Output LOW Voltage at I _{OL} = 4mA		0.45	.223	.242	.265	-.008	0	.005	Volts
300	Power-Supply Current, all Outputs HIGH		31	18.0	21.2	24.2	-.20	0	.60	mA
302	Power-Supply Current, all Outputs LOW		32	19.5	22.9	25.7	-.20	0	.80	mA

TABLE V
1000 HOUR LIFE TEST DATA
FOR Am74LS174

Parameter	Typical Initial Value	Average Percent Change
Substrate Leakage	0 μ A	0
Min V _{CC} to Function	2.19V	0
Schottky Voltage @ 100 μ A	.484V	0
V _{OH} , Output High Voltage	2.92V	-.11
I _{SC} , Short-Circuit Output Current	26.38mA	0.3
I _{CEX} , Output Leakage	7.85 μ A	0
V _{OL1} , Output Low Voltage @ 4mA	.270V	0.05
V _{OL2} , Output Low Voltage @ 8mA	.328V	0
I _{IL} , Input Low Current	171 μ A	-0.9
V _{th} , Input Threshold Voltage	1.015V	0.2
I _{IH} , Input Leakage	.04 μ A	-12
I _{IB} , Input Breakdown Current	0 μ A	0
V _{IC} , Input Clamp Diode	.894V	0.6
I _{CC} , Supply Current @ 5.5V	13.54mA	0.3
I _{CM} , Supply Current @ 7V	18.46mA	0
t _{pd+} , CP to Q _O	11.99ns	0
t _{pd-} , CP to Q _O	11.44ns	0.1

TABLE VI
1000 HOUR LIFE TEST DATA
FOR Am74LS157

Parameter	Typical Initial Value	Average Percent Change
Substrate Leakage	.7 μ A	0
Min V _{CC} to Function	2.84V	0.09
Schottky Voltage @ 100 μ A	.452V	0.2
V _{OH} , Output HIGH Voltage 2.92V	2.92V	0
I _{SC} , Short-Circuit Output Current	26.4mA	0.3
I _{CEX} , Output Leakage	0 μ A	0
V _{OL1} , Output Low Voltage @ 4mA	.277V	0
V _{OL2} , Output Low Voltage @ 8mA	.331V	0
I _{IL} , Input Low Current	313 μ A	0.3
V _{th} , Input Threshold Voltage	1.08V	0
I _{IH} , Input Leakage	0.5 μ A	0
I _{IB} , Input Breakdown Current	0 μ A	0
V _{IC} , Input Clamp Diode	.837V	0
I _{CC} , Supply Current @ 5.5V	10.1mA	0
I _{CM} , Supply Current @ 7V	13.48mA	0
t _{pd+} , 1A to 1Y	5.1ns	0.3
t _{pd-} , 1A to 1Y	5.4ns	0

TABLE VII
125°C LIFE TEST DATA

Device	Test Type	No. Parts	Hours on Test	Thousand Unit Hours	Failures	70°C Equivalent Failure Rate*
Test Pattern I	Design	22	11,000 Hr.	242	0	0.008% per thousand hours
Test Pattern II	Design	22	10,000 Hr.	220	0	0.009
74LS174	Param. Drift	20	2,000 Hr.	80	0	0.02
74LS175	Param. Drift	20	2,000 Hr.	80	0	0.02
25LS161	Param. Drift	100	1,000 Hr.	100	0	0.02
74LS157	Group C Life	77	1,000 Hr.	77	0	0.02
74LS161	Group C Life	77	1,000 Hr.	77	0	0.02
74LS193	Group C Life	77	1,000 Hr.	77	0	0.02
TOTAL DEVICE – 371				491	0	0.001

*Equivalent failure rate at 70°C calculated from Poisson distribution of a zero defect sample and activation energy of 1.0 ev for acceleration factor. Equivalent failure is not greater than the quoted value at 90% confidence.

LOW-POWER SCHOTTKY LS-MSI/LSI DATA SHEETS

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DEFINITION OF A.C. SWITCHING TERMS

(All switching times are measured at the 1.3V logic level unless otherwise noted.)

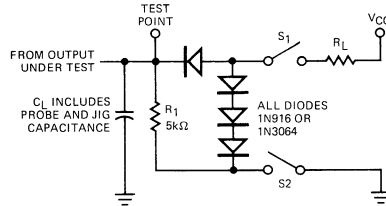
- f_{MAX}** The highest operating clock frequency.
- t_{PLH}** The propagation delay time from an input change to an output LOW-to-HIGH transition.
- t_{PHL}** The propagation delay time from an input change to an output HIGH-to-LOW transition.
- t_{PW}** Pulse width. The time between the leading and trailing edges of a pulse.
- t_r** Rise time. The time required for a signal to change from 10% to 90% of its measured values.
- t_f** Fall time. The time required for a signal to change from 90% to 10% of its measured values.
- t_s** Set-up time. The time interval for which a signal must be applied and maintained at one input terminal before an active transition occurs at another input terminal.
- t_h** Hold time. The time interval for which a signal must be retained at one input after an active transition occurs at another input terminal.
- t_R** Release time. The time interval for which a signal may be indeterminate at one input terminal before an active transition occurs at another input terminal. (The release time falls within the set-up time interval and is specified by some manufacturers as a negative hold time).
- t_{HZ}** HIGH to disable. The delay time from a control input change to the three-state output HIGH-level to high-impedance transition (measured at 0.5V change).
- t_{LZ}** LOW to disable. The delay time from a control input change to the three-state output LOW-level to high-impedance transition (measured at 0.5V change).
- t_{ZH}** Enable HIGH. The delay time from a control input change to the three-state output high-impedance to HIGH-level transition.
- t_{ZL}** Enable LOW. The delay time from a control input change to the three-state output high-impedance to LOW-level transition.

DEFINITION OF D.C. TERMS

- H** HIGH, applying to a HIGH voltage level.
- L** LOW, applying to a LOW voltage level.
- I** Input.
- O** Output.
- Negative Current** Current flowing out of the device.
- Positive Current** Current flowing into the device.
- I_{IL}** LOW-level input current with a specified LOW-level voltage applied.
- I_{IH}** HIGH-level input current with a specified HIGH-level voltage applied.
- I_{OL}** LOW-level output current.
- I_{OH}** HIGH-level output current.
- I_{SC}** Output short-circuit source current.
- I_{CC}** The supply current drawn by the device from the V_{CC} power supply.
- V_{IL}** Logic LOW input voltage.
- V_{IH}** Logic HIGH input voltage.
- V_{OL}** LOW-level output voltage with I_{OL} applied.
- V_{OH}** HIGH-level output voltage with I_{OH} applied.

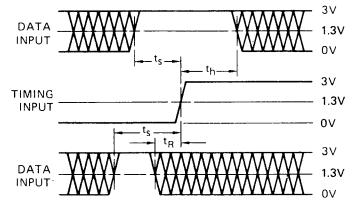
**LOW-POWER SCHOTTKY
PARAMETER MEASUREMENTS**

LOAD TEST CIRCUIT FOR THREE-STATE OUTPUTS



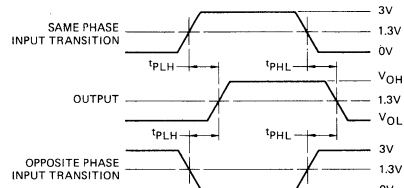
Note: For standard totem-pole outputs, remove R₁; S₁ and S₂ closed.

SET-UP, HOLD, AND RELEASE TIMES

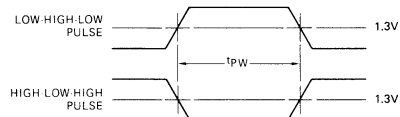


Notes: 1. Diagram shown for HIGH data only. Output transition may be opposite sense.
2. Cross hatched area is don't care condition.

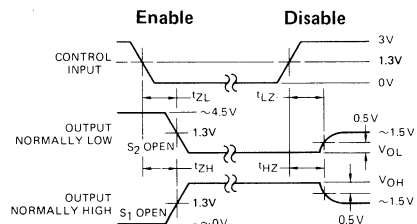
PROPAGATION DELAY



PULSE WIDTH



ENABLE AND DISABLE TIMES



Notes: 1. Diagram shown for Input Control Enable-LOW and Input Control Disable-HIGH.
2. S₁ and S₂ of Load Circuit are closed except where shown.

Note: 1. Pulse Generator for All Pulses: Rate ≤ 1.0MHz; Z₀ = 50Ω;
tr ≤ 15ns; tf ≤ 6ns.

Am25LS07·Am25LS08

Hex/Quad Parallel D Registers With Register Enable

DISTINCTIVE CHARACTERISTICS

- 4-bit and 6-bit parallel registers
- Common Clock and Common Enable
- Positive edge triggered D flip flops
- Am25LS d. c. parameters including:
 $V_{OL} = 0.45V$ at $I_{OL} = 8mA$
 Fan-out over military range = 22
 440 μA source current
- Second sourced by TI as 54LS/74LS378 and 379
- 100% product assurance screening to MIL-STD-883 requirements

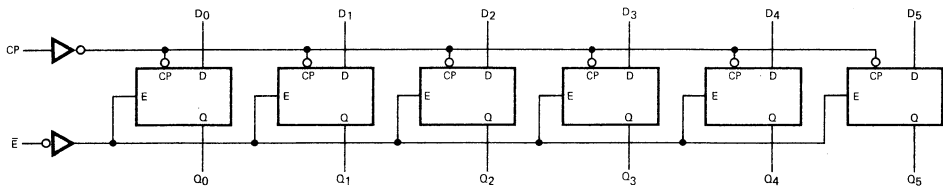
FUNCTIONAL DESCRIPTION

The Am25LS07 is a 6-bit Low Power Schottky register with a buffered common register enable. The Am25LS08 is a 4-bit register with a buffered common register enable. The devices are similar to the Am54LS/74LS174 and Am54LS/74LS175 but feature the common register enable rather than common clear.

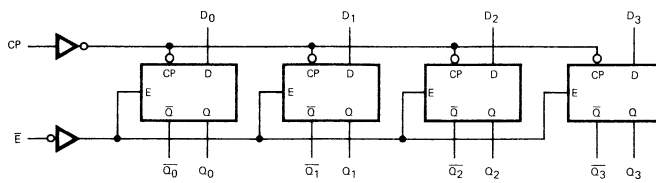
Both registers will find application in digital systems where information is associated with a logic gating signal. When the enable is LOW, data on the D inputs is stored in the register on the positive going edge of the clock pulse. When the enable is HIGH, the register will not change state regardless of the clock or data input transitions.

LOGIC DIAGRAMS

Am25LS07

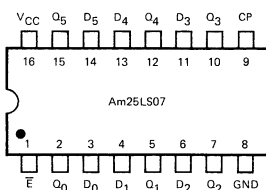


Am25LS08

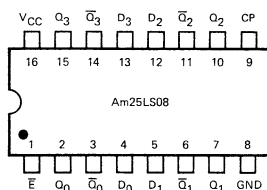


CONNECTION DIAGRAMS Top Views

Am25LS07



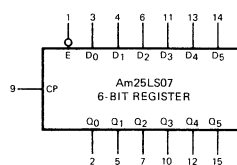
Am25LS08



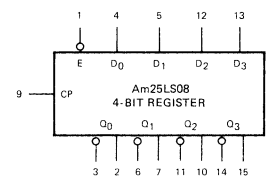
Note: Pin 1 is marked for orientation.

LOGIC SYMBOLS

Am25LS07



Am25LS08



$V_{CC} = \text{Pin } 16$
 $GND = \text{Pin } 8$

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH}$ or V_{IL}	COM'L	2.7	3.4		Volts
			MIL	2.5	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4\text{mA}$			0.4	Volts
			$I_{OL} = 8\text{mA}$			0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	COM'L			0.8	Volts
			MIL			0.7	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	Clock, \bar{E}			-0.36	mA
			Others			-0.24	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	Clock, \bar{E}			20	μA
			Others			14	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)	LS07		16	22	mA
			LS08		11	18	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Outputs open; enable grounded; data inputs at 4.5V, measured after a momentary ground, then 4.5V applied to the clock input.

3

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

SWITCHING CHARACTERISTICS $(T_A = +25^\circ\text{C}, V_{CC} = 5.0\text{V})$

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	Clock to Output		13	20	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}	Clock to Output		13	20	ns	
t_{pw}	Clock Pulse Width	17			ns	
t_s	Data	20			ns	
t_e	Enable	30			ns	
t_f	Data	5.0			ns	
t_h	Enable	5.0			ns	
f_{max} (Note 1)	Maximum Clock Frequency	40	65		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

**SWITCHING CHARACTERISTICS
OVER OPERATING RANGE***

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to Output		30		35	ns	$C_L = 50pF$ $R_L = 2.0k\Omega$
t_{PHL}	Clock to Output		30		35	ns	
t_{pw}	Clock Pulse Width	26		30		ns	
t_s	Data	30		35		ns	
t_s	Enable	43		50		ns	
t_h	Data	11		12		ns	
t_h	Enable	11		12		ns	
f_{max} (Note 1)	Maximum Clock Frequency	30		25		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

D_i The D flip-flop data inputs.

E Enable. When the enable is LOW, data on the D_i inputs is transferred to the Q_i outputs on the LOW-to-HIGH clock transition. When the enable is HIGH, the Q_i outputs do not change regardless of the data or clock input transitions.

CP Clock Pulse for the register. Enters data on the LOW-to-HIGH transition.

Q_i The TRUE register outputs.

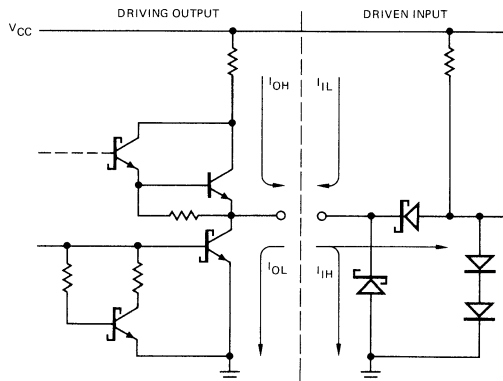
Q̄_i The complement register outputs

FUNCTION TABLE

Inputs			Outputs	
\bar{E}	D _i	CP	Q _i	Q̄ _i
H	X	X	NC	NC
L	X	H	NC	NC
L	X	L	NC	NC
L	L	↑	L	H
L	H	↑	H	L

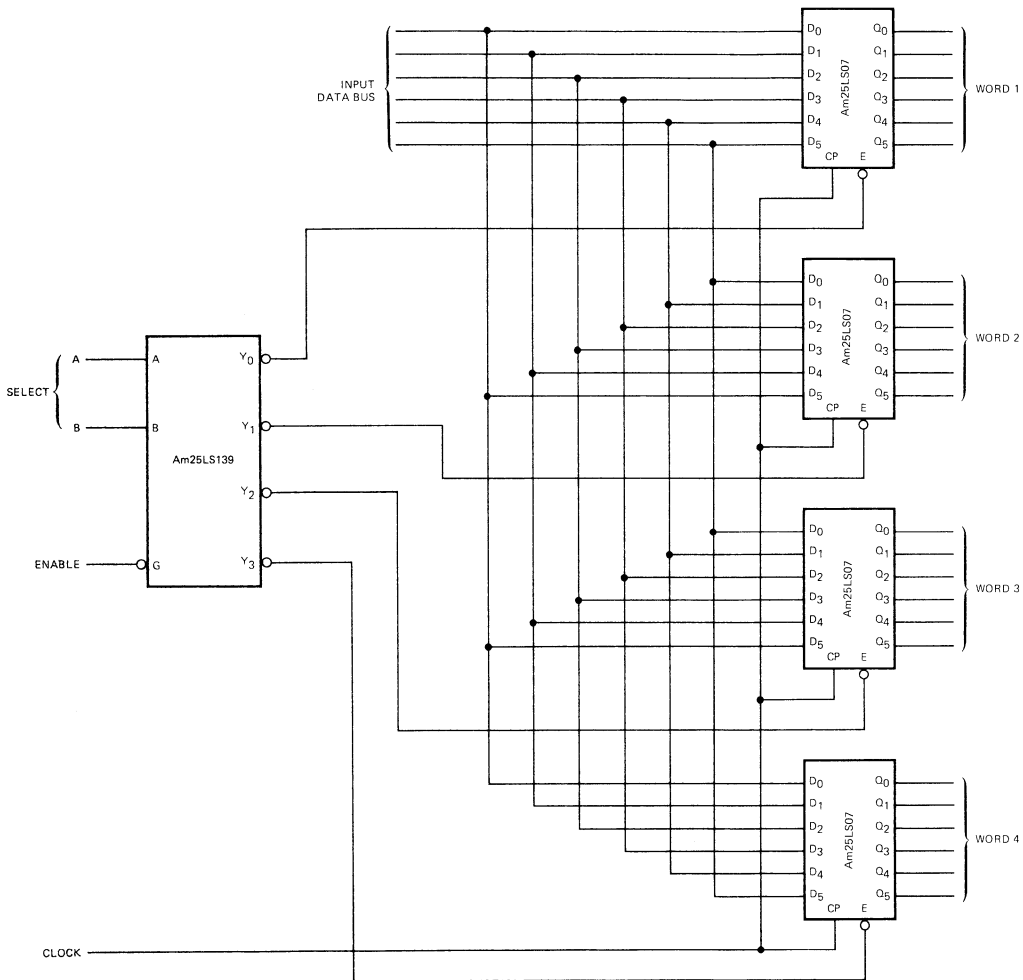
H = HIGH NC = No Change
L = LOW X = Don't Care
↑ = LOW-to-HIGH Transition
Q̄_i on Am25LS08 Only

**LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**



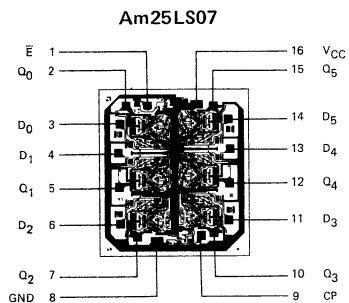
Note: Actual current flow direction shown.

APPLICATION

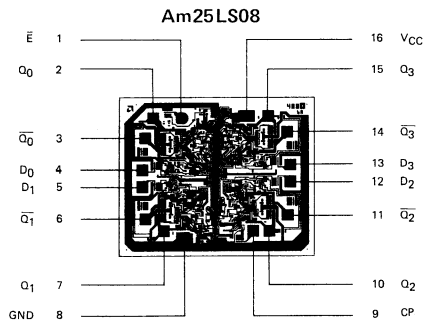


Selective Register Loading of Data on Synchronous Clock.

Metallization and Pad Layout



DIE SIZE 0.075" X 0.084"



DIE SIZE 0.075" X 0.061"

3

Am25LS09

Quad Two-Input, High-Speed Register

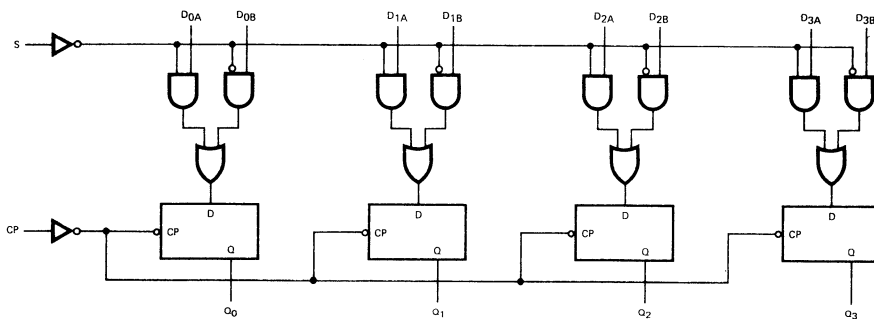
DISTINCTIVE CHARACTERISTICS

- 4-bit register accepts data from one-of-two 4-bit input fields
- Edge triggered clock action
- Second sourced by T.I. as 54LS/74LS399
- Am25LS d.c. parameters including:
 - $V_{OL} = 0.45V$ at $I_{OL} = 8mA$
 - Fan-out over military range = 22
 - $440\mu A$ source current
- 100% product assurance screening to MIL-STD-883 requirements

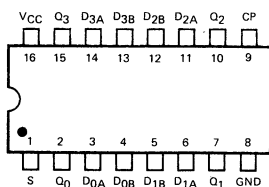
FUNCTIONAL DESCRIPTION

The Am25LS09 is a dual port four-bit register using advanced Low Power Schottky technology to reduce the effect of transistor storage time. The register consists of four D flip-flops with a buffered common clock, and a two-input multiplexer at the input of each flip-flop. A common select line, S, controls the four multiplexers. Data on the four inputs selected by the S line is stored in the four flip-flops at the clock LOW-to-HIGH transition. When the S input is LOW, the D_{iA} input data will be stored in the register. When the S input is HIGH, the D_{iB} input data will be stored in the register.

LOGIC DIAGRAM

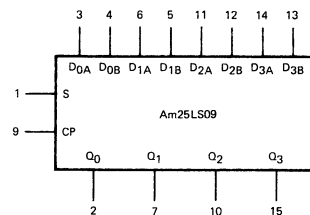


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\%$	(MIN. = 4.75V MAX. = 5.25V)
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\%$	(MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -440 μ A V _{IN} = V _{IH} or V _{IL}	COM'L	2.7	3.4	Volts
			MIL	2.5	3.4	
V _{OL}	Output LOW Voltage	V _{CC} = MIN. V _{IN} = V _{IH} or V _{IL}	I _{OL} = 4mA		0.4	Volts
			I _{OL} = 8mA		0.45	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.5	Volts
I _{IL}	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.4V	Clock, S		-0.36	mA
			Others		-0.24	
I _{IH}	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V	Clock, S		20	μ A
			Others		14	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 7.0V			0.1	mA
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.	-15		-85	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 4)		11	18	mA

- Notes: 1. For conditions shown as MIN. or MAX. use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25 $^\circ$ C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Measured with Select and Clock inputs at 4.5V; all data inputs at 0V; all outputs open.

3

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65 $^\circ$ C to +150 $^\circ$ C
Temperature (Ambient) Under Bias	-55 $^\circ$ C to +125 $^\circ$ C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 V to +7.0 V
DC Voltage Applied to Outputs for High Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +7.0 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

SWITCHING CHARACTERISTICS(T_A = +25 $^\circ$ C, V_{CC} = 5.0V)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t _{PLH}	Clock to Q HIGH		13	20	ns	C _L = 15pF, R _L = 2.0k Ω
t _{PHL}	Clock to Q LOW		13	20	ns	
t _{pw}	Clock Pulse Width				ns	
t _s	Data Set-up Time	17			ns	
t _l	Select Input Set-up Time	20			ns	
t _h	Data Hold Time	30			ns	
t _h	Select Input Hold Time	5			ns	
f _{max} (Note 1)	Maximum Clock Frequency	0			MHz	

- Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

**SWITCHING CHARACTERISTICS
OVER OPERATING RANGE***

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to Q HIGH		30		35	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}	Clock to Q LOW		30		35	ns	
t_{PW}	Clock Pulse Width	26		30		ns	
t_S	Data Set-up Time	30		35		ns	
t_{s}	Select Input Set-up Time	43		50		ns	
t_h	Data Hold Time	11		12		ns	
t_h	Select Input Hold Time	4		5		ns	
f_{max} (Note 1)	Maximum Clock Frequency	30		25		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

D_{0A}, D_{1A}, D_{2A}, D_{3A} The "A" word into the two-input multiplexer of the D flip-flops.

D_{0B}, D_{1B}, D_{2B}, D_{3B} The "B" word into the two-input multiplexer of the D flip-flops.

Q₀, Q₁, Q₂, Q₃ The outputs of the four D-type flip-flops of the register.

S Select. When the select is LOW, the A word is applied to the D inputs of the flip-flops. When the select is HIGH the B word is applied to the D inputs of the flip-flops.

CP Clock Pulse. Clock pulse for the register. Enters data on the LOW-to-HIGH transition of the clock line.

FUNCTION TABLE

SELECT S	CLOCK CP	DATA D _{iA}	INPUTS D _{iB}	OUTPUT Q _i
L	↑	L	X	L
L	↑	H	X	H
H	↑	X	L	L
H	↑	X	H	H

H = HIGH Voltage Level

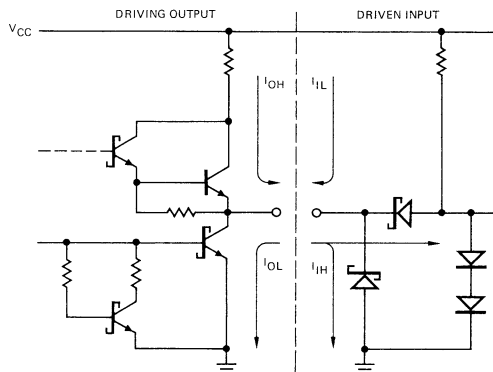
X = Don't Care

↑ = LOW-to-HIGH Transition

L = LOW Voltage Level

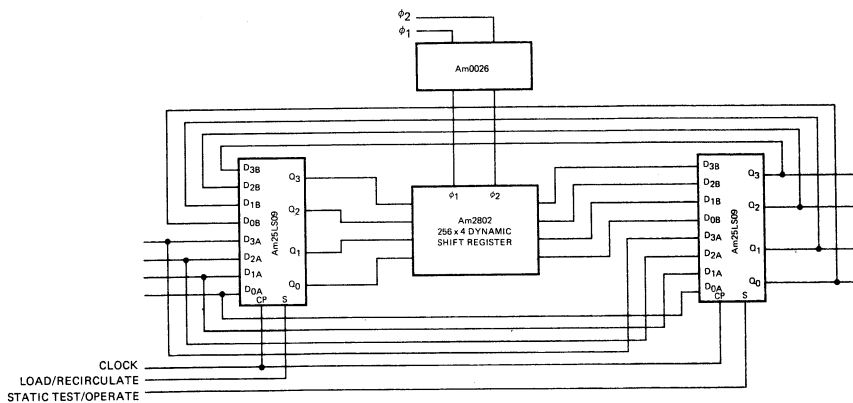
i = 0, 1, 2, or 3

**Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**

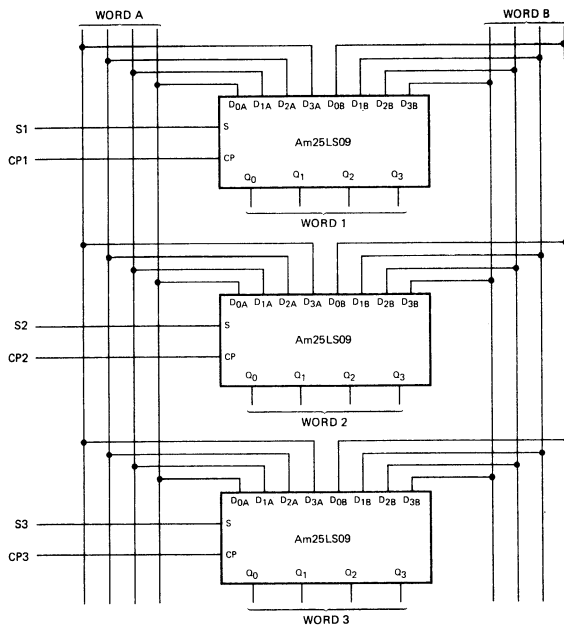


Note: Actual current flow direction shown.

APPLICATIONS

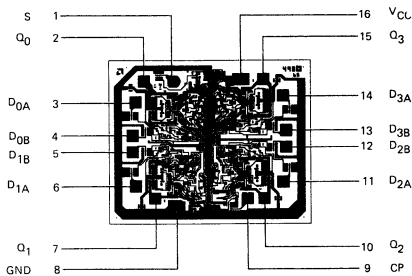


Am25LS09 used in 256 x 4 memory system with load/recirculate control, and 1 x 4 static test capability for the system. MOS interface is one load at each end. This circuit is especially useful in digital filtering where special algorithms require a static single step operation for testing purposes.



Am25LS09 used to store a word from either data bus A or data bus B.

Metallization and Pad Layout



DIE SIZE 0.075" X 0.061"

3

Am25LS14

8-Bit Serial/Parallel Two's Complement Multiplier

DISTINCTIVE CHARACTERISTICS

- Two's complement multiplication without correction
- Magnitude only multiplication
- Cascadable for any number of bits
- 8-bit parallel multiplicand data input
- 25MHz minimum clock frequency
- Second sourced by T.I. as the SN54LS/74LS384
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

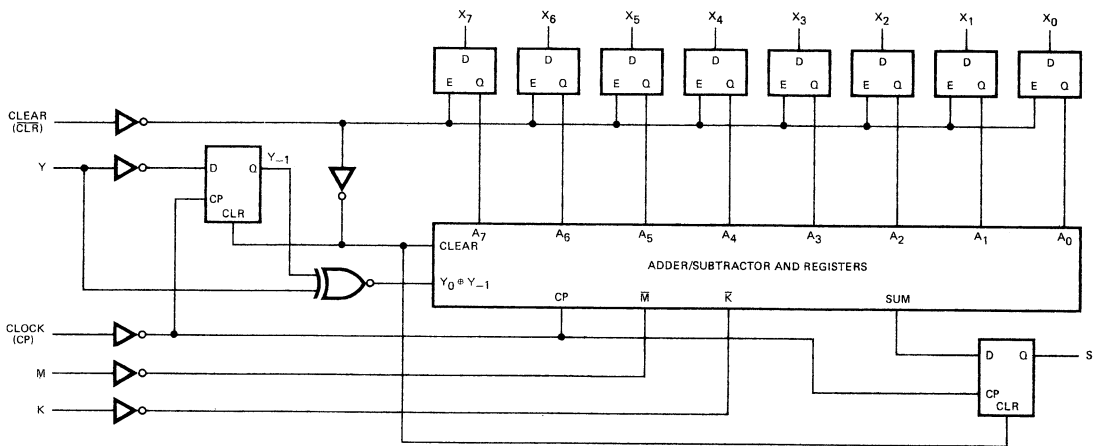
The Am25LS14 is an 8-bit by 1-bit sequential logic element that performs digital multiplication of two numbers represented in two's complement form to produce a two's complement product without correction by using Booth's algorithm internally. The device accepts an 8-bit multiplicand (X input) and stores this data in eight internal latches. The X latches are controlled via the clear input. When the clear input is LOW, all internal flip-flops are cleared and the X latches are opened to accept new multiplicand data. When the clear input is HIGH, the latches are closed and are insensitive to X input changes.

The multiplier word data is passed by the Y input in a serial bit stream — least significant bit first. The product is clocked out the S output least significant bit first.

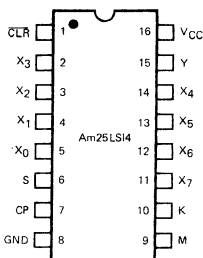
The multiplication of an m-bit multiplicand by an n-bit multiplier results in an m + n bit product. The Am25LS14 must be clocked for m + n clock cycles to produce this two's complement product. Likewise, the n-bit multiplier (Y-input) sign bit data must be extended for the remaining m-bits to complete the multiplication cycle.

The device also contains a K input so that devices can be cascaded for longer length X words. The sum (S) output of one device is connected to the K input of the succeeding device when cascading. Likewise, a mode input (M) is used to indicate which device contains the most significant bit. The mode input is wired HIGH or LOW depending on the position of the 8-bit slice in the total X word length.

LOGIC DIAGRAM

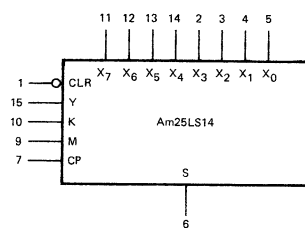


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



VCC = Pin 16
GND = Pin 8

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am25LS14XC	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\% (\text{COM'L})$	MIN. = 4.75V	MAX. = 5.25V
Am25LS14XM	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\% (\text{MIL})$	MIN. = 4.5V	MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)			Units
			Min.	Max.	Max.	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -1.0\text{mA}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4	Volts
			COM'L	2.7	3.4	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 8.0\text{mA}$		0.4	Volts
			$I_{OL} = 12\text{mA}$		0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.2	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	X, M		-0.48	mA
			K, $\overline{\text{CLR}}$		-1.2	
			CP		-1.6	
			Y		-3.2	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	X, M		20	μA
			K, $\overline{\text{CLR}}$		30	
			CP		40	
			Y		80	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 5.5\text{V}$			1.0	mA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$		91	155	mA

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Duration of the short circuit test should not exceed one second.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +5.5V
Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am25LS14

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	Clock to Output		13	20	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			13	20		
t_{pHL}	Clear to Output		17	25	ns	
t_s	Y to Clock	32			ns	
t_h		0				
t_s	K to Clock	18			ns	
t_h		0				
t_s	X_i to Clear	13			ns	
t_h		0				
t_{pw}	Clock (HIGH)	15			ns	
	Clock (LOW)	15				
t_{pw}	Clear Pulse Width	20			ns	
t_s	Clear Recovery Time (Inactive State)	18			ns	
f_{max} (Note 1)	Maximum Clock Frequency	25	30		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to Output		24		27	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			27		30		
t_{pHL}	Clear to Output		33		37	ns	
t_s	Y to Clock	38		45		ns	
t_h		0		0			
t_s	K to Clock	24		30		ns	
t_h		0		0			
t_s	X_i to Clear	19		23		ns	
t_h		0		0			
t_{pw}	Clock (HIGH)	18		22		ns	
	Clock (LOW)	18		22			
t_{pw}	Clear Pulse Width	33		38		ns	
t_s	Clear Recovery Time (Inactive State)	20		30		ns	
f_{max} (Note 1)	Maximum Clock Frequency	20		15		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

X₀, X₁, X₂, X₃, X₄, X₅, X₆, X₇ The eight data inputs for the multiplicand (X) data.

Y The serial input for the multiplier (Y) data—least significant bit first.

S The serial output for the product of X • Y—least significant bit first.

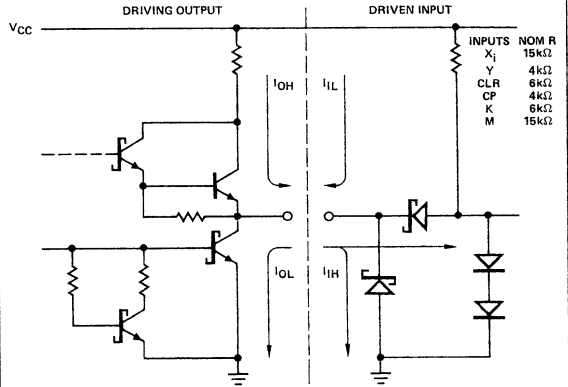
CP Clock. The buffered common clock input for the serial/parallel multiplier. All functions occur on the LOW-to-HIGH transition of the clock.

CLR Clear. The buffered common clear for all flip-flops within the device. When the clear is LOW all flip-flops are cleared. Also the buffered X-input latch enable. When the clear input is LOW, the X latches will accept new X-input data.

K The sum expansion input to the serial/parallel multiplier. Allows for cascading devices.

M The mode control input for the most significant bit of the multiplier. It is used in conjunction with cascading to determine the most significant bit.

INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



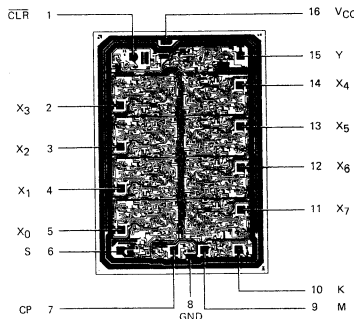
Note: Actual current flow direction shown.

FUNCTION TABLE

INPUTS						INTERNAL	OUTPUT	FUNCTION
CLR	CP	K	M	X _i	Y	Y ₋₁	S	
-	-	L	L	-	-	-	-	Most Significant Multiplier Device
-	-	CS	H	-	-	-	-	Devices Cascaded in Multiplier String
L	-	-	-	OP	-	L	L	Load New Multiplicand and Clear Internal Sum and Carry Registers
H	-	-	-	-	-	-	-	Device Enabled
H	↑	-	-	-	L	H	AR	Shift Sum Register
H	↑	-	-	-	L	H	AR	Add Multiplicand to Sum Register and Shift
H	↑	-	-	-	H	L	AR	Subtract Multiplicand from Sum Register and Shift
H	↑	-	-	-	H	H	AR	Shift Sum Register

H = HIGH
 L = LOW
 ↑ = LOW-to-HIGH transition
 CS = Connected to S output of higher order device
 OP = X_i latches open for new data (i = 0, 7)
 AR = Output as required per Booth's algorithm

Metallization and Pad Layout



DIE SIZE 0.097" X 0.137"

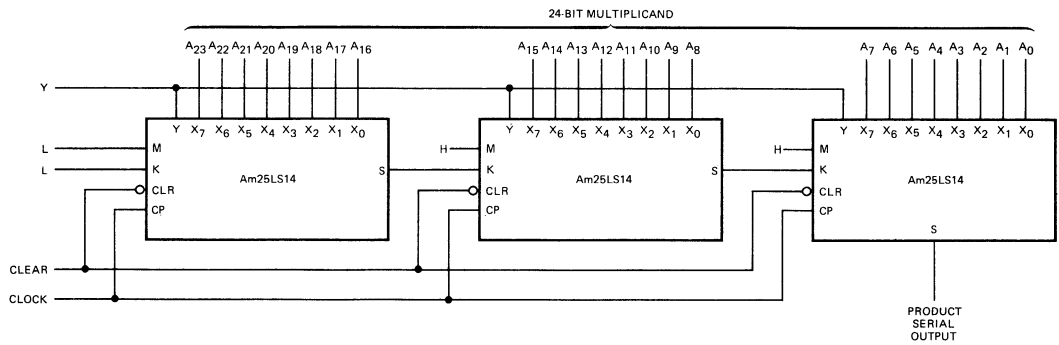
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ORDERING INFORMATION

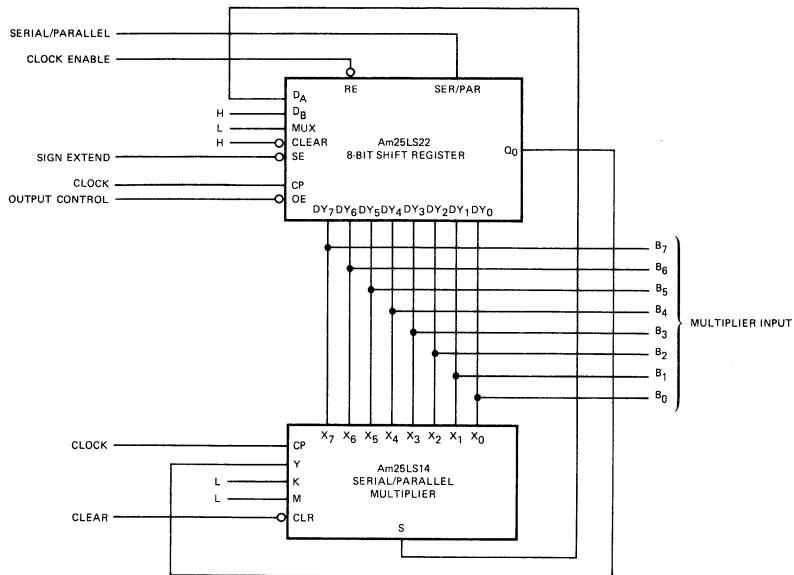
Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM25LS14PC
Hermetic DIP	0°C to +70°C	AM25LS14DC
Dice	0°C to +70°C	AM25LS14XC
Hermetic DIP	-55°C to +125°C	AM25LS14DM
Hermetic Flat Pak	-55°C to +125°C	AM25LS14FM
Dice	-55°C to +125°C	AM25LS14XM

APPLICATIONS

See also Digital Signal Processing Applications Section for more information.



Basic 24-Bit Serial/Parallel Connection



8-Bit by 8-Bit Multiplier, Bus Organized, with 8-Bit Truncated Product

Am25LS15

Quad Serial Adder/Subtractor

DISTINCTIVE CHARACTERISTICS

- Four independent adder/subtractors
- Use with two's complement arithmetic
- Magnitude only addition/subtraction
- Second sourced by T.I. as Am54LS/74LS385
- 100% product assurance screening to MIL-STD-883 requirements

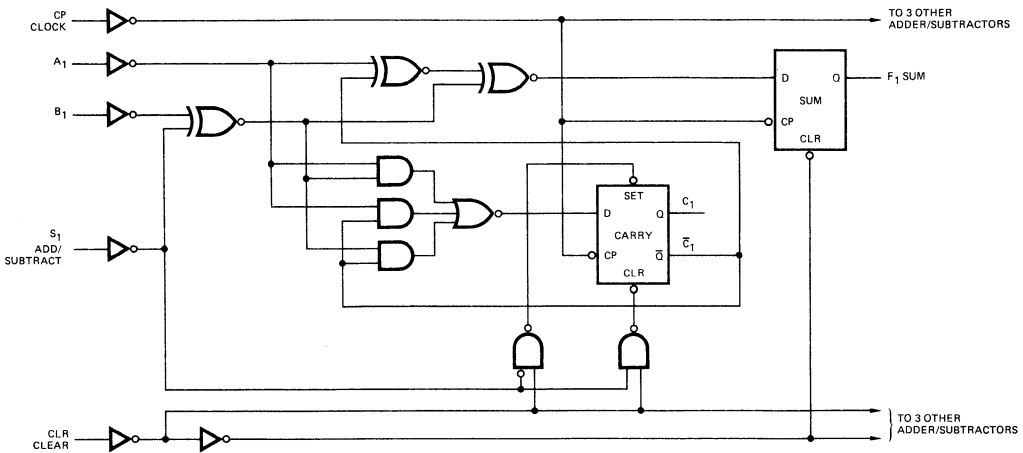
FUNCTIONAL DESCRIPTION

The Am25LS15 is a serial two's complement adder/subtractor designed for use in association with the Am25LS14 serial/parallel two's complement multiplier. This device can also be used for magnitude only or one's complement addition or subtraction.

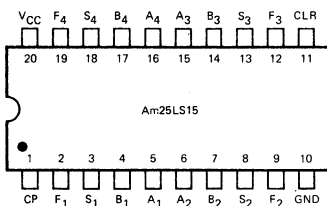
Four independent adder/subtractors are provided with common clock and clear inputs. The add function is A plus B and the subtract function is A minus B. The clear function sets the internal carry function to logic zero in the add mode and to logic one in subtract mode. This least significant carry is self propagating in the subtract mode as long as zeroes are applied to the A and B inputs at the LSB's. All internal flip-flops change state on the LOW-to-HIGH clock transition.

The Am25LS15 is particularly useful for recursive or non-recursive digital filtering or butterfly networks in Fast Fourier Transforms.

LOGIC DIAGRAM (One of Four Similar Functions)

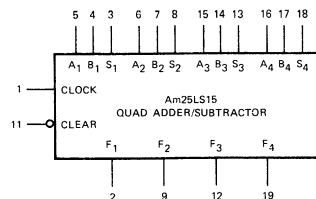


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 20
GND = Pin 10

3

Am25LS15

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\%$	(MIN. = 4.75V MAX. = 5.25V)
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\%$	(MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5		Volts
			COM'L	2.7		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.4	Volts
			$I_{OL} = 8.0\text{mA}$		0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.36	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		48	75	mA

- Notes: 1. For conditions shown as Min. or Max., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. All inputs HIGH, measured after a LOW-to-HIGH clock transition.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to + V_{CC} max
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	Clock to Output		14	22	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			14	22		
t_{PHL}	Clear to Output		20	30	ns	
t_s	A, B, S	10			ns	
t_h		0				
t_s	Clear Recovery	25			ns	
t_h	Clear Hold Time	0			ns	
t_{pw}	Clock	HIGH	17		ns	
		LOW	17			
t_{pw}	Clear LOW	20			ns	
f_{max} (Note 1)	Maximum Clock Frequency	30	40		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on the t_r , t_f , pulse width or duty cycle.

**SWITCHING CHARACTERISTICS
OVER OPERATING RANGE***

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to Output		33		38	ns	$C_L = 50pF$ $R_L = 2.0k\Omega$
t_{PHL}			33		38		
t_{PHL}	Clear to Output		43		50	ns	
t_s	A, B, S	17		20		ns	
t_h			4		5		
t_s	Clear Recovery	37		42		ns	
t_h	Clear Hold Time	4		5		ns	
t_{pw}	Clock	HIGH	26		30	ns	
		LOW	26		30		
t_{pw}	Clear LOW	30		35		ns	
f_{max} (Note 1)	Maximum Clock Frequency	23		20		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

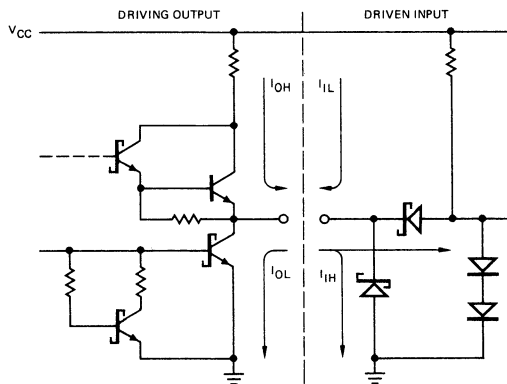
- A₁, A₂, A₃, A₄** The "A" input into each adder/subtractor
- B₁, B₂, B₃, B₄** The "B" input into each adder/subtractor
- S₁, S₂, S₃, S₄** The add subtract control for each adder/subtractor. When S is LOW, the F function is A+B. When S is HIGH, the F function is A-B.
- F₁, F₂, F₃, F₄** The four independent serial outputs of the adder/subtractor.
- CP Clock** The clock input for the device. All internal flip-flops change state on the LOW-to-HIGH transition.
- CLR Clear** When the clear input is LOW, the four independent adder/subtractors are asynchronously reset. The sum flip-flop is always set to logic "0". The carry flip-flop is set to logic "0" in the add mode and logic "1" in the subtract mode.

FUNCTION TABLE

External Inputs				Internal Point		Output		Function
CP	CLR	S	A	B	C	C ₁	F	
X	L	L	X	X	L	L	L	Clear
X	L	H	X	X	H	H	L	
L	H	X	X	X	NC	NC	NC	Add
H	H	X	X	X	NC	NC	NC	
↑	H	L	L	L	L	L	L	
↑	H	L	L	L	H	L	H	
↑	H	L	L	H	L	L	L	Subtract
↑	H	L	H	L	L	L	L	
↑	H	L	H	L	H	H	L	
↑	H	L	H	H	L	H	L	
↑	H	H	L	L	L	L	L	Subtract
↑	H	H	L	L	H	H	L	
↑	H	H	L	H	L	L	L	
↑	H	H	L	H	L	H	L	
↑	H	H	H	L	H	H	H	
↑	H	H	H	H	L	L	H	

- C = Data In the Carry Flip-Flop Before the Clock Transition
- C₁ = Data In the Carry Flip-Flop After the Clock
- X = Don't Care
- NC = No Change
- H = HIGH
- L = LOW
- ↑ = LOW-to-HIGH Transition

**Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**



Note: Actual current flow direction shown.

3

APPLICATIONS

The normal butterfly network associated with the Cooley-Tukey Fast Fourier Transform (FFT) algorithm is shown below. Here we assume A, B, C, D and W are all complex numbers such that:

$$A = A_R + jA_I$$

$$B = B_R + jB_I$$

$$W = W_R + jW_I$$

The outputs C and D are also complex numbers and are evaluated as:

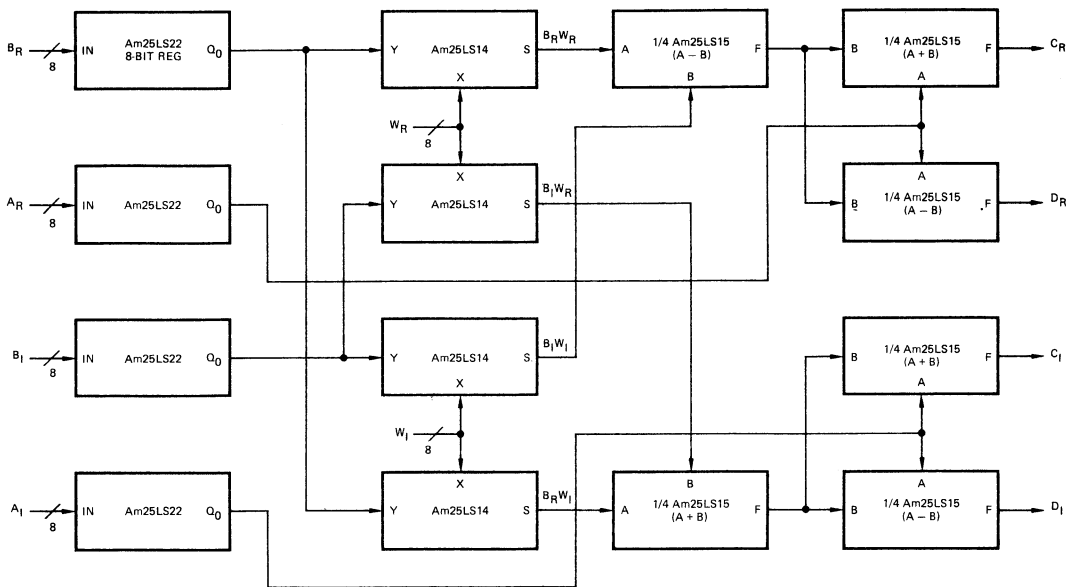
$$C = C_R + jC_I = (A_R + B_R W_R - B_I W_I) + j(A_I + B_R W_I + B_I W_R)$$

$$D = C_R + jD_I = (A_R - B_R W_R + B_I W_I) + j(A_I - B_R W_I - B_I W_R)$$

The four multiplications can be implemented using four Am25LS14 serial-parallel multipliers (the appropriate number of bits must, of course, be used). The additions and the subtractions are implemented using the Am25LS15 quad serial adder/subtractors. This diagram depicts only the basic data flow; binary weighting of the numbers, rounding, truncation, etc. must be handled as required by the individual design parameters.

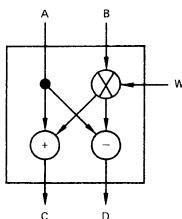
Also see Digital Signal Processing Applications section for more information.

FAST FOURIER TRANSFORM (FFT) BUTTERFLY

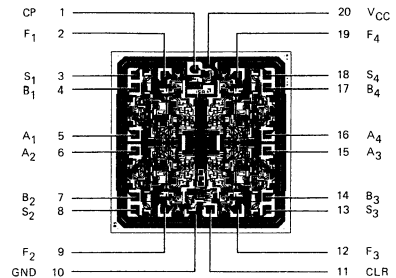


An FFT butterfly connection for complex arithmetic inputs and outputs.

Functional Diagram for FFT Butterfly Connection



Metallization and Pad Layout



DIE SIZE 0.095" X 0.095"

Am25LS22

8-Bit Serial/Parallel Register With Sign Extend

DISTINCTIVE CHARACTERISTICS

- Three-state outputs with multiplexed input
- Multiplexed serial data input
- Sign extend function
- Second sourced by T.I. as Am54LS/74LS322
- 100% product assurance screening to MIL-STD-883 requirements

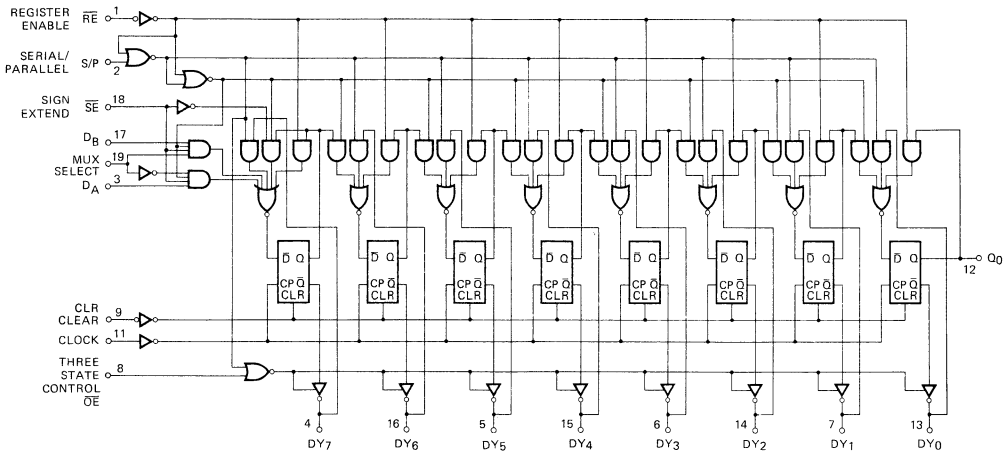
FUNCTIONAL DESCRIPTION

The Am25LS22 is an eight-bit serial/parallel register built using advanced Low-Power Schottky processing. The device features an eight-bit parallel multiplexed input/output port to provide improved bit density in a 20-pin package. Data may also be loaded into the device in a serial manner from either input D_A or D_B . A serial output, Q_0 , is also provided.

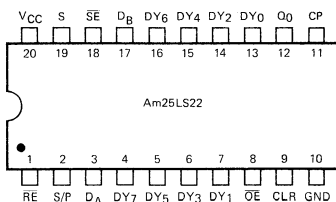
The Am25LS22 is specifically designed for operation with the Am25LS14 serial/parallel two's complement multiplier and provides the sign extend function required for this device.

When the Register Enable (\overline{RE}) input is HIGH, the register will retain its current contents. Synchronous parallel loading is accomplished by applying a LOW to \overline{RE} and applying a LOW to the Serial/Parallel (S/P) input. This places the three-state outputs in the high-impedance state independent of \overline{OE} and allows data that is applied on the input/output lines (DY_i) to be clocked into the register. When the S/P input is HIGH, the device will shift right. The Sign Extend (\overline{SE}) input is used to repeat the sign in the Q_7 flip-flop. This occurs whenever \overline{SE} is LOW when the SHIFT mode is selected. When \overline{SE} is high, the serial two-input multiplexer is enabled. Thus, either D_A or D_B can be selected to load data serially. The register changes state on the LOW-to-HIGH transition of the clock. A clear input (CLR) is used to asynchronously reset all flip-flops when a LOW is applied.

LOGIC DIAGRAM

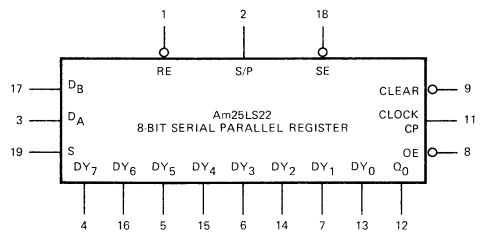


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 20
GND = Pin 10

Am25LS22

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units		
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$Q_0, I_{OH} = -440\mu\text{A}$	MIL	2.5		Volts	
				COM'L	2.7			
			$DY_i, I_{OH} = -1.0\text{mA}$	MIL	2.4			
				COM'L	2.4			
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.4	Volts		
			$I_{OL} = 8.0\text{mA}$		0.45			
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts		
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts		
			COM'L		0.8			
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts		
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	\overline{SE}		-1.08	mA		
			S		-0.72			
			Others		-0.36			
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$ (Except DY_i)	\overline{SE}		60	μA		
			S		40			
			Others		20			
I_I	Input HIGH Current	$V_{CC} = \text{MAX.},$ (Except DY_i)	$V_{IN} = 7.0\text{V}$	$\overline{OE}, S/P, RE, CP, CLR$		0.1	mA	
				\overline{SE}		0.3		
			$V_{IN} = 5.5\text{V}$	S		0.2		
				Others		0.1		
I_{OZ}	Off State (High Impedance) Output Current (DY_i)	$V_{CC} = \text{MAX.}$	$V_O = 2.4\text{V}$		40	μA		
			$V_O = 0.4\text{V}$		-100			
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA		
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$		40	65	mA		

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}, 25^\circ\text{C}$ ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to V_{CC} max.
DC Input Voltage ($\overline{OE}, S/P, RE, CP, CLR$)	-0.5V to +7.0V
DC Input Voltage (Others)	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

SWITCHING CHARACTERISTICS ($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	Clock to DY_i		16.5	24	ns	$R_L = 2.0\text{k}\Omega$, $C_L = 15\text{pF}$
t_{PHL}			18	26		
t_{PHL}	Clear to DY_i		23	30	ns	
t_{PLH}			16.5	24		
t_{PHL}	Clock to Q_0		18	26	ns	
t_{PHL}			23	30		
t_{ZH}	\overline{OE} to DY_i		13	21	ns	$R_L = 2.0\text{k}\Omega$, $C_L = 5\text{pF}$
t_{ZL}			18	26		
t_{HZ}			13	21		
t_{LZ}			18	26		
t_{ZH}	SER/PAR to DY_i		18	26	ns	$R_L = 2.0\text{k}\Omega$, $C_L = 15\text{pF}$
t_{ZL}			23	32		
t_{HZ}			18	26		
t_{LZ}			23	32		
t_s	RE to Clock	20			ns	$R_L = 2.0\text{k}\Omega$, $C_L = 15\text{pF}$
t_s	SE to Clock	10				
t_s	S to Clock	15				
t_s	D_A and D_B to Clock	15				
t_s	DY_i (Load) to Clock	15				
t_s	Clear Recovery to Clock	8.0				
t_s	S/P to Clock	15				
t_h	Any Input	0				
t_h	Clear Hold	0			ns	
t_{pw}	Clock	HIGH	8.0		ns	
		LOW	8.0			
t_{pw}	Clear	20			ns	
f_{max} (Note 1)	Maximum Clock Frequency	35	50		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

3

FUNCTION TABLE

Mode	INPUTS							OUTPUTS								
	Clear	Register Enable	Serial/Parallel	Sign Extend	Mux Select	\overline{OE}^*	Clock	DY ₇	DY ₆	DY ₅	DY ₄	DY ₃	DY ₂	DY ₁	DY ₀	Q ₀
Clear	L	X	X	X	X	L	X	L	L	L	L	L	L	L	L	L
	L	X	X	X	X	H	X	Z	Z	Z	Z	Z	Z	Z	Z	L
Parallel Load	H	L	L	X	X	X	↑	D ₇	D ₆	D ₅	D ₄	D ₃	D ₂	D ₁	D ₀	D ₀
Shift Right	H	L	H	H	L	L	↑	D _A	Y _{7n}	Y _{6n}	Y _{5n}	Y _{4n}	Y _{3n}	Y _{2n}	Y _{1n}	Y _{1n}
	H	L	H	H	H	L	↑	D _B	Y _{7n}	Y _{6n}	Y _{5n}	Y _{4n}	Y _{3n}	Y _{2n}	Y _{1n}	Y _{1n}
Sign Extend	H	L	H	L	X	L	↑	Y _{7n}	Y _{7n}	Y _{6n}	Y _{5n}	Y _{4n}	Y _{3n}	Y _{2n}	Y _{1n}	Y _{1n}
Hold	H	H	X	X	X	L	↑	NC	NC	NC	NC	NC	NC	NC	NC	NC

L = LOW

H = HIGH

↑ = Clock LOW-to-HIGH Transition

NC = No Change

X = Don't Care

Z = High-Impedance Output State

*When the OE input is HIGH, all input/output terminals are at the high-impedance state; sequential operation or clearing of the register is not affected.

D₇, D₆ . . . D₀ = the level of the steady-state input at the respective DY_n terminal is loaded into the flip-flop while the flip-flop outputs (except Q₀) are isolated from the DY_n terminal.

D_A, D_B = the level of the steady-state inputs to the serial multiplexer input.

Y_{7n}, Y_{6n} . . . Y_{0n} = the level of the respective Q_n flip-flop prior to the last Clock LOW-to-HIGH transition.

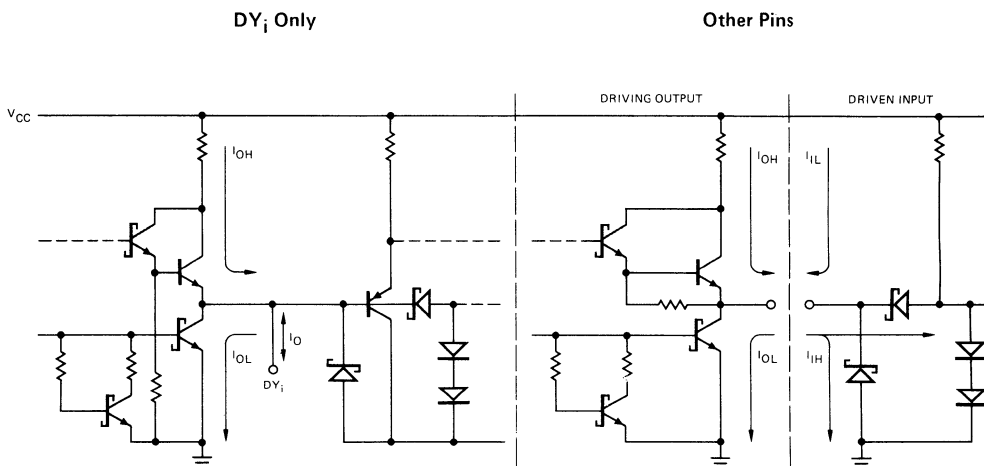
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$			
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to DY_i		35		41	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			38		44		
t_{PHL}	Clear to DY_i		43		50	ns	
t_{PLH}		Clock to Q_0		35			
t_{PHL}			38		44		
t_{PHL}	Clear to Q_0		43		50	ns	
t_{ZH}		OE to DY_i		32			
t_{ZL}			38		44		
t_{HZ}			28		31		
t_{LZ}			34		39		
t_{ZH}	SER/PAR to DY_i		38		44	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{ZL}			46		53		
t_{HZ}			34		39		$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{LZ}			42		48		
t_s	RE to Clock	30		35		$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$	
t_s	SE to Clock	17		20	ns		
t_s	S to Clock	24		27			
t_s	D_A and D_B to Clock	24		27			
t_s	DY_i (Load) to Clock	24		27			
t_s	Clear Recovery to Clock	15		17			
t_s	S/P to Clock	24		27	ns		
t_h	Any Input	4		5			
t_h	Clear Hold	4		5	ns		
t_{pw}	Clock	HIGH	15		17		ns
		LOW	15		17		
t_{pw}	Clear	30		35	ns		
f_{max} (Note 1)	Maximum Clock Frequency	26		23		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

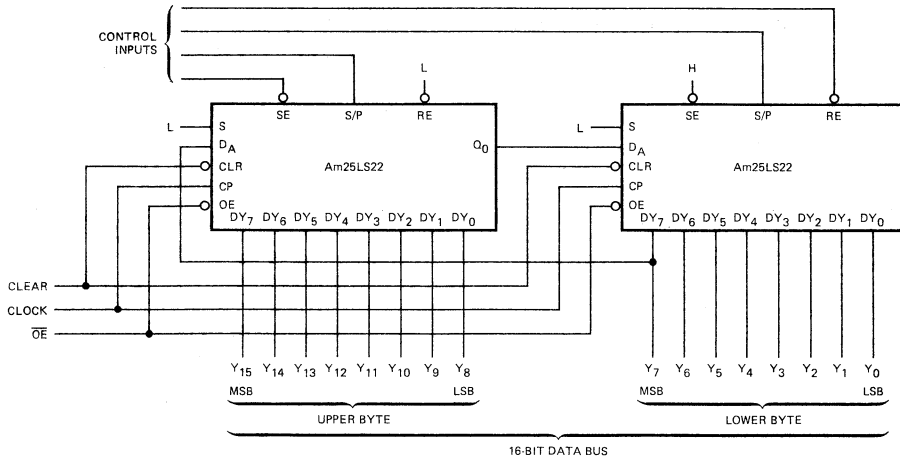
DEFINITION OF FUNCTIONAL TERMS

- DY_i** The multiplexed parallel input/output port to the device. Data may be parallel loaded into the register or data can be read in parallel from the register on these pins. These outputs can be forced to the high-impedance state, $i = 0$ through 7.
- Q₀** The continuous output from the Q₀ flip-flop of the register. This output is used for serial shifting.
- \overline{RE}** Register Enable. When \overline{RE} is LOW, the register functions are enabled. When \overline{RE} is HIGH, the register functions (parallel load, shift right and sign extend) are inhibited.
- S/P** Serial/Parallel. When S/P is LOW, the register can be synchronously parallel loaded. This input forces the register output buffers to the high-impedance state independent of the \overline{OE} input. When S/P is HIGH, the register contents are shifted right on the clock LOW-to-HIGH transition.
- \overline{SE}** Sign Extend. When the \overline{SE} input is LOW, the contents of the Q₇ flip-flop will be repeated in the Q₇ flip-flop as the register is shifted right. When \overline{SE} is HIGH, the two-input multiplexer (D_A and D_B) is enabled to enter data during the serial shift right. The Q₇ flip-flop (DY₇) is normally considered the MSB of the register for arithmetic definitions.
- D_A, D_B** The serial inputs to the device.
- S** Multiplexer Select. When S is LOW, the D_A serial input is selected. When S is HIGH, the D_B serial input is selected.
- CLR** Clear. The asynchronous clear to the register. When the clear is LOW, the outputs of the flip-flops are set LOW independent of all other inputs. When the clear is HIGH, the register will perform the selected function.
- CP** Clock. The clock pulse for the register. Register operations occur on the LOW-to-HIGH transition of the clock pulse.
- \overline{OE}** Output Control. When the \overline{OE} input is HIGH, the eight DY_i outputs are in the high-impedance state. When \overline{OE} is LOW, data in the eight flip-flops will be present at the register parallel outputs unless S/P is LOW.

INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS

Note: Actual current flow direction shown.

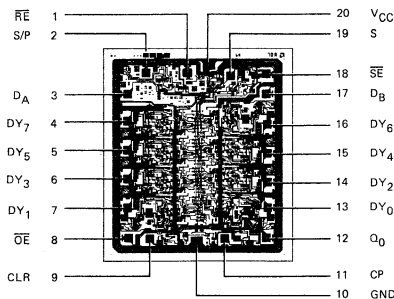
APPLICATION



SYSTEM OPERATION	Am25LS22 UPPER BYTE				Am25LS22 LOWER BYTE				FUNCTION
	\overline{SE}	S/P	\overline{RE}	\overline{OE}	\overline{SE}	S/P	\overline{RE}	\overline{OE}	Description
Load lower byte and extend lower byte sign to upper byte	H	H	L	X	X	L	L	X	Load from Bus
	L	H	L	H	X	X	H	H	7 clock cycles to extend sign
Load upper byte and extend upper byte sign while shifting value to lower byte position	X	L	L	X	X	X	X	X	Load from Bus
	H	H	L	H	H	H	L	H	8 clock cycles to extend upper byte sign and shift upper byte into lower byte position
Read 16-bit word to Bus	X	X	X	L	X	X	X	L	Unload

Two Am25LS22 8-bit registers can be used to perform the sign extend associated with two's complement 8-bit bytes for arithmetic operations in a 16-bit machine. If the upper byte value is to be used, it is shifted to the lower bit positions and its sign is extended. If the lower byte value is to be used, it is held in place while the sign is extended downward from the MSB position of the upper byte.

Metalization and Pad Layout



DIE SIZE 0.096" X 0.112"

Am25LS23

8-Bit Shift/Storage Register with Synchronous Clear

DISTINCTIVE CHARACTERISTICS

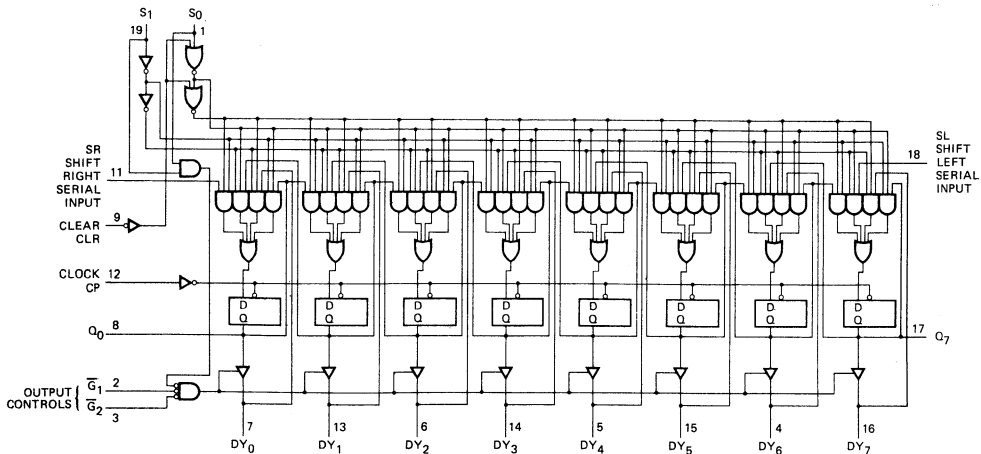
- Synchronous clear
- Three-state outputs
- Common input/output pins
- Cascadable shifting
- Second sourced by T.I. as 54LS/74LS323
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

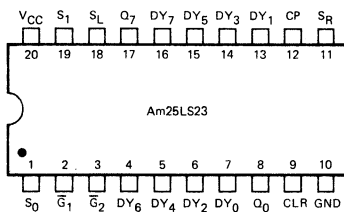
The Am25LS23 is an 8-bit universal shift/storage register with 3-state outputs. The function is similar to the Am25LS299 with the exception of a synchronous clear function. Parallel load inputs and register outputs are multiplexed to allow the use of a 20-pin package. Separate continuous outputs are also provided for flip-flops Q_0 and Q_7 .

Four modes of operation are possible — Hold (store), Shift-left, Shift-right and Load Data. The Am25LS23 has a typical shift frequency of 50MHz. The Am25LS23 is packaged in a standard 20-pin package.

LOGIC DIAGRAM

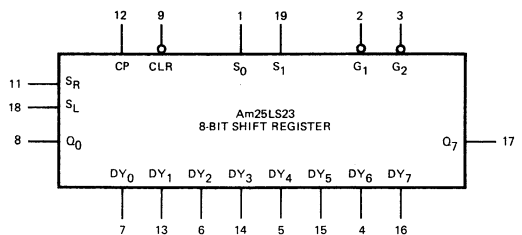


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 20
GND = Pin 10

ELECTRICAL CHARACTERISTICS The following conditions apply unless otherwise specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{OL}	Q_0, Q_7	$I_{OH} = -440\mu\text{A}$	MIL	2.5		Volts
					COM'L	2.7		
		DY ₀ -DY ₇	MIL, $I_{OH} = -1.0\text{mA}$		2.4			
			COM'L, $I_{OH} = -2.6\text{mA}$		2.4			
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}		$I_{OL} = 4.0\text{mA}$		0.25	0.4	Volts
				$I_{OL} = 8.0\text{mA}$		0.35	0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs				2.0		Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			MIL		0.7	Volts
					COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$					-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			S_0, S_1		-0.8	mA
					All others		-0.4	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$ (Except DY _i)			S_0, S_1		40	μA
					All others		20	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.},$ (Except DY _i)		$V_{IN} = 7\text{V}$	S_0, S_1		0.2	mA
				$V_{IN} = 5.5\text{V}$	$\bar{G}_1, \bar{G}_2, \text{CLR}, \text{CP}$		0.1	
					Others		0.1	
I_{OZ}	Off-State (High Impedance) Output Current	$V_{CC} = \text{MAX.}$			$V_O = 0.4\text{V}$		-100	μA
					$V_O = 2.4\text{V}$		40	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$				-15		mA
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)				38	60	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time.
 4. I_{CC} - measured with clock input HIGH and output controls HIGH.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to V_{CC} max.
DC Input Voltage ($S_0, S_1, \bar{G}_1, \bar{G}_2, \text{CLR}, \text{CP}$)	-0.5V to +7.0V
DC Input Voltage (Others)	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

SWITCHING CHARACTERISTICS ($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	Clock to Q_0 or Q_7		18	26	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			23	28		
t_{PLH}	Clock to DY _i		18	26	ns	
t_{PHL}			21	28		
t_s	S_1, S_0 Set-up Prior to Clock	12			ns	
t_s	DY _i or S_R, S_L Set-up Prior to Clock	12			ns	
t_{PW}	Pulse Width (Clock)	15			ns	
t_s	Clear to Clock	15			ns	
t_{ZH}	$S_1, S_0, \bar{G}_1, \bar{G}_2$ to DY _i		18	30	ns	
t_{ZL}			20	30		
t_{LZ}	$S_1, S_0, \bar{G}_1, \bar{G}_2$ to DY _i		22	33	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{HZ}			16	23		
f_{max}	Maximum Clock Frequency (Note 1)	35	50		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

**SWITCHING CHARACTERISTICS
OVER OPERATING RANGE***

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$			
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to Q_0 or Q_7		38		44	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			40		47		
t_{PLH}	Clock to DY_i		38		44	ns	
t_{PHL}			40		47		
t_s	S_1, S_0 Set-up Prior to Clock	20		23		ns	
t_s	DY_i or S_R, S_L Set-up Prior to Clock	20		23		ns	
t_{pw}	Pulse Width (Clock)	24		27		ns	
t_s	Clear to Clock	24		27		ns	
t_{ZH}	$S_1, S_0, \bar{G}_1, \bar{G}_2$ to DY_i		43		50	ns	
t_{ZL}				43			50
t_{LZ}	$S_1, S_0, \bar{G}_1, \bar{G}_2$ to DY_i		43		50	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{HZ}				30			
f_{max}	Maximum Clock Frequency (Note 1)	26		23		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

S_R	Shift right data input to Q_7	S₀, S₁	Mode selection control lines used to control input (output during load) conditions
S_L	Shift left data input to Q_0	\bar{G}_1, \bar{G}_2	Active LOW input to control three-state output in active LOW AND configuration
Clear	Active LOW synchronous input forcing the Q_0 through Q_7 register to see LOW conditions, visible only if outputs are enabled	Q₀, Q₇	The only two direct outputs; used to cascade shift operations
Clock	A LOW-to-HIGH transition will result in the register changing state to next state as described by mode and input data condition	DY₀-DY₇	Input/Output line dependent on mode and output control. Input only with mode select LOAD. Output in all other modes but subject to output select (\bar{G}_1, \bar{G}_2).

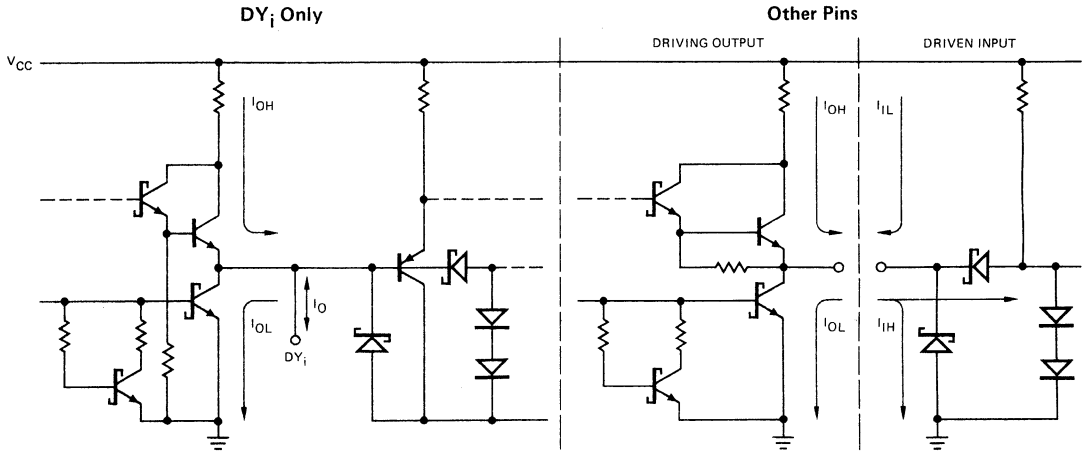
TRUTH TABLE

FUNCTION		INPUTS						OUTPUTS		INPUTS/OUTPUTS									
		S _R	S _L	CLEAR	CLOCK	S ₀	S ₁	\bar{G}_1	\bar{G}_2	Q ₀	Q ₇	DY ₀	DY ₁	DY ₂	DY ₃	DY ₄	DY ₅	DY ₆	DY ₇
Clear		X	X	L	↑	(Note 1)	L	L	L	L	L	L	L	L	L	L	L	L	L
Output Control		X	X	X	X	X	X	H	L	NC	NC	Z	Z	Z	Z	Z	Z	Z	Z
		X	X	X	X	X	X	L	H	NC	NC	Z	Z	Z	Z	Z	Z	Z	Z
		X	X	X	X	X	X	H	H	NC	NC	Z	Z	Z	Z	Z	Z	Z	Z
M	Hold	X	X	H	X	L	L	L	L	NC	NC	NC	NC	NC	NC	NC	NC	NC	NC
	Load (Note 2)	X	X	H	↑	H	H	L	L	A	H	A	B	C	D	E	F	G	H
O	Shift Right	L	X	H	↑	H	L	L	L	L	DY ₆	L	DY ₀	DY ₁	DY ₂	DY ₃	DY ₄	DY ₅	DY ₆
D	Shift Right	H	X	H	↑	H	L	L	L	H	DY ₆	H	DY ₀	DY ₁	DY ₂	DY ₃	DY ₄	DY ₅	DY ₆
E	Shift Left	X	L	H	↑	L	H	L	L	DY ₁	L	DY ₁	DY ₂	DY ₃	DY ₄	DY ₅	DY ₆	DY ₇	L
	Shift Left	X	H	H	↑	L	H	L	L	DY ₁	H	DY ₁	DY ₂	DY ₃	DY ₄	DY ₅	DY ₆	DY ₇	H

L = LOW Z = High Impedance ↑ = Transition LOW-to-HIGH
H = HIGH X = Don't Care NC = No Change

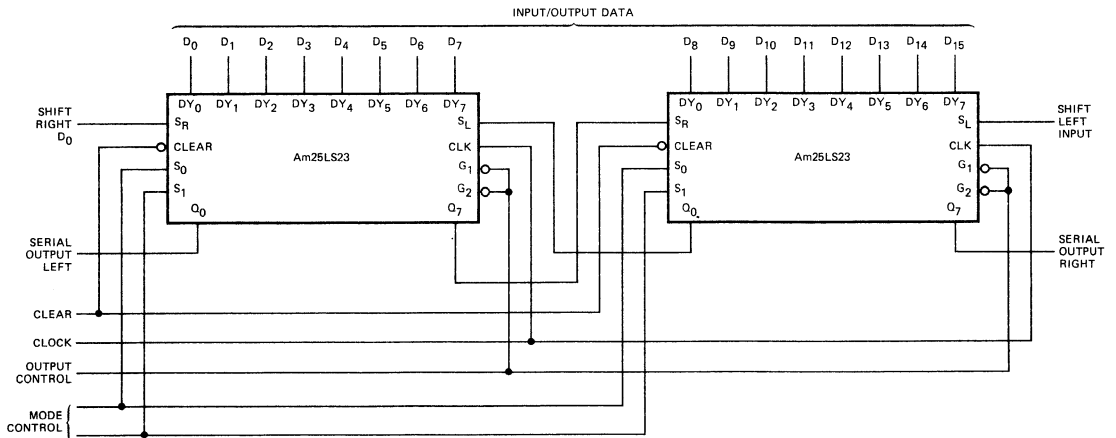
Notes: 1. Either LOW to observe outputs.
2. In this mode DY_i are inputs.

INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



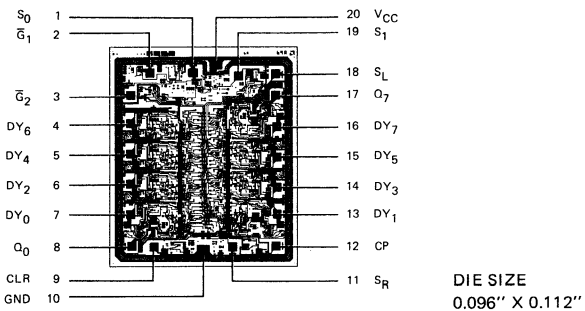
Note: Actual current flow direction shown.

APPLICATION



16-Bit Cascaded Parallel Load/Unload Shift Right/Left Register.

Metallization and Pad Layout



Am25LS138 • Am54LS/74LS138

3-Line To 8-Line Decoder/Demultiplexer

DISTINCTIVE CHARACTERISTICS

- Inverting and non-inverting enable inputs
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL}
 - Twice the fan-out over military range
 - 440 μ A source current
- 100% product assurance screening to MIL-STD-883 requirements

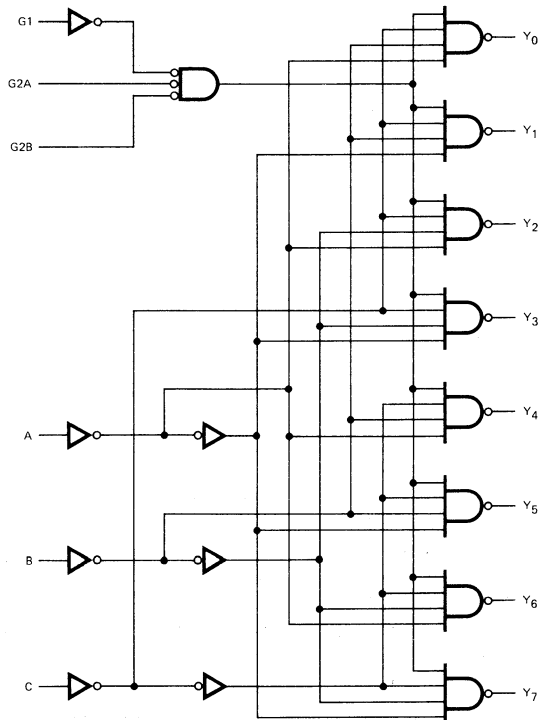
FUNCTIONAL DESCRIPTION

The Am25LS138 is a 3-line to 8-line decoder/demultiplexer fabricated using advanced Low-Power Schottky technology. The decoder has three buffered select inputs A, B and C that are decoded to one of eight Y outputs.

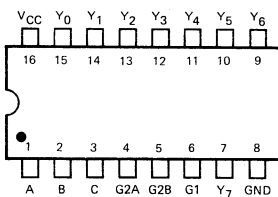
One active-HIGH and two active-LOW enables can be used for gating the decoder or can be used with incoming data for demultiplexing applications. When the enable input function is in the disable state, all eight Y outputs are HIGH regardless of the A, B and C select inputs.

The Am54LS/74LS138 is a standard performance version of the Am25LS138. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAM

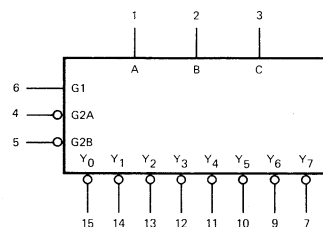


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

Am25LS/54LS/74LS138

ELECTRICAL CHARACTERISTICS Am25LS138

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4\text{mA}$			0.4	Volts
			$I_{OL} = 8\text{mA}$			0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.36	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)		6.3	10	mA	

ELECTRICAL CHARACTERISTICS Am54LS/74LS138

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	All, $I_{OL} = 4\text{mA}$			0.4	Volts
			74LS only, $I_{OL} = 8\text{mA}$			0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.36	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)		6.3	10	mA	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. Outputs enabled and open.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Two Level Delay		10	15		13	20	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}	Select to Output		14	21		27	41		
t_{PLH}	Three Level Delay		15	23		18	27		
t_{PHL}	Select to Output		18	27		26	39		
t_{PLH}	G2A or G2B		10	15		12	18		
t_{PHL}	to Output		15	23		21	32		
t_{PLH}	G1 to Output		12	18		17	26		
t_{PHL}			18	27		25	38		

Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Two Level Delay		24		27	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}	Select to Output		31		36		
t_{PLH}	Three Level Delay		34		39		
t_{PHL}	Select to Output		39		45		
t_{PLH}	G2A or G2B		24		27		
t_{PHL}	to Output		34		39		
t_{PLH}	G1 to Output		27		32		
t_{PHL}			39		45		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

3

DEFINITION OF FUNCTIONAL TERMS

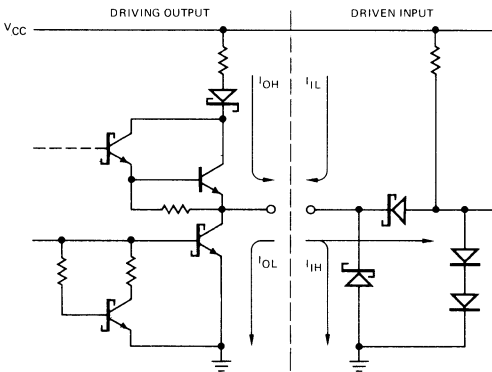
A, B, C Select. The three select inputs to the decoder.

G1 The active-HIGH enable input. A LOW on the G1 input forces all Y outputs HIGH regardless of any other inputs.

G2A, G2B The active-LOW enable input. A HIGH on either the G2A or G2B input forces all Y outputs HIGH regardless of any other inputs.

Y₀, Y₁, Y₂, Y₃, Y₄, Y₅, Y₆, Y₇ The eight decoder outputs.

Am25LS • Am54LS/74LS
LOW POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS



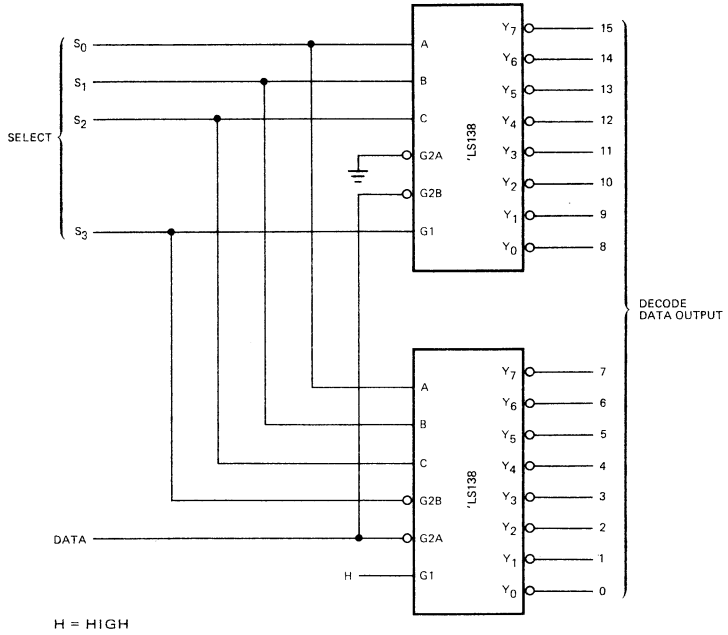
Note: Actual current flow direction shown.

FUNCTION TABLE

Inputs		Outputs											
		Enable			Select			Outputs					
G1	G2A	G2B	C	B	A	Y ₀	Y ₁	Y ₂	Y ₃	Y ₄	Y ₅	Y ₆	Y ₇
L	X	X	X	X	X	H	H	H	H	H	H	H	H
X	H	X	X	X	X	H	H	H	H	H	H	H	H
X	X	H	X	X	X	H	H	H	H	H	H	H	H
H	L	L	L	L	L	L	L	L	L	L	L	L	L
H	L	L	L	L	H	H	L	H	H	H	H	H	H
H	L	L	L	H	L	H	H	L	H	H	H	H	H
H	L	L	L	H	H	H	H	L	H	H	H	H	H
H	L	L	L	H	L	H	H	H	H	L	H	H	H
H	L	L	L	H	L	H	H	H	H	H	L	H	H
H	L	L	L	H	H	L	H	H	H	H	H	L	H
H	L	L	L	H	H	H	H	H	H	H	H	H	L

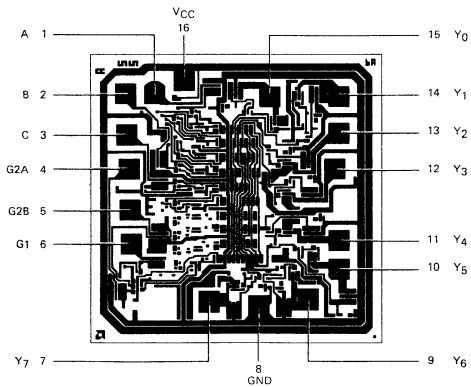
H = HIGH L = LOW X = Don't care

APPLICATION



ONE-OF-SIXTEEN DEMULTIPLEXER

Metallization and Pad Layout



DIE SIZE 0.065" X 0.065"

Am25LS139 • Am54LS/74LS139

Dual 2-Line To 4-Line Decoder/Demultiplexer

DISTINCTIVE CHARACTERISTICS

- Two independent decoders/demultiplexers
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL}
 - Twice the fan-out over military range
 - 440 μ A source current
- 100% product assurance screening to MIL-STD-883 requirements

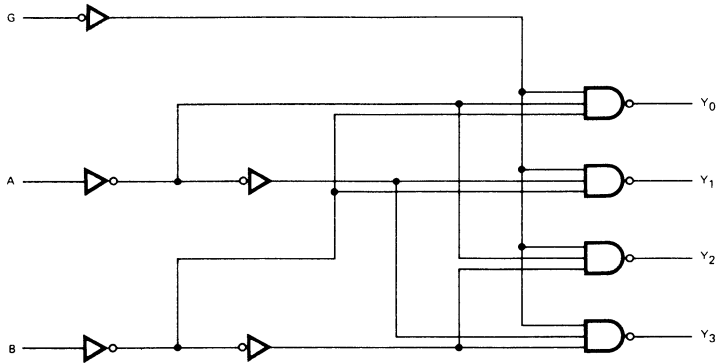
FUNCTIONAL DESCRIPTION

The Am25LS139 is a dual 2-line to 4-line decoder/demultiplexer unit fabricated using advanced Low-Power Schottky technology. Each decoder has two buffered select inputs A and B which are decoded to one of four Y outputs.

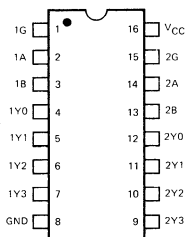
An active LOW enable can be used for gating or can be used as a data input for demultiplexing applications. When the enable is HIGH, all four Y outputs are HIGH, regardless of the A and B inputs.

The Am54LS/74LS139 is a standard performance version of the Am25LS139. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAM
(One Decoder Shown)

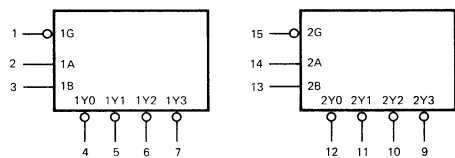


CONNECTION DIAGRAM
Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

3

Am25LS/54LS/74LS139

Am25LS139

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)		Max.	Units
			Min.	Max.		
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -440μA V _{IN} = V _{IH} or V _{IL}	MIL	2.5	3.4	Volts
			COM'L	2.7	3.4	
V _{OL}	Output LOW Voltage	V _{CC} = MIN., V _{IN} = V _{IH} or V _{IL}	I _{OL} = 4mA		0.4	Volts
			I _{OL} = 8mA		0.45	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.5	Volts
I _{IL}	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.4V			-0.36	mA
I _{IH}	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			20	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 7.0V			0.1	mA
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.	-15		-85	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 4)		6.8	11	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CC} is measured with all outputs enabled and open.

MAXIMUM RATINGS(Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

Am54LS/74LS139

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -400 μ A V _{IN} = V _{IH} or V _{IL}	MIL	2.5	3.4	Volts
			COM'L	2.7	3.4	
V _{OL}	Output LOW Voltage	V _{CC} = MIN., V _{IN} = V _{IH} or V _{IL}	All, I _{OL} = 4mA		0.4	Volts
			74LS only, I _{OL} = 8mA		0.5	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.5	Volts
I _{IL}	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.4V			-0.36	mA
I _{IH}	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			20	μ A
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 7.0V			0.1	mA
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.	-15		-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 4)		6.8	11	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25 $^\circ$ C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CC} is measured with all outputs enabled and open.

SWITCHING CHARACTERISTICS

(T_A = +25 $^\circ$ C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	Select to Output,		8	12		13	20	ns	C _L = 15pF R _L = 2.0k Ω
t _{PHL}	2 Levels of Delay		12	18		22	33		
t _{PLH}	Select to Output,		13	20		18	29	ns	
t _{PHL}	3 Levels of Delay		14	21		25	38		
t _{PLH}	Enable to Output,		8	12		16	24	ns	
t _{PHL}	2 Levels of Delay		12	18		21	32		

Am25LS ONLY

SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	Select to Output		20		23	ns	C _L = 50pF R _L = 2.0k Ω
t _{PHL}	2 Levels of Delay		27		32		
t _{PLH}	Select to Output		30		35	ns	
t _{PHL}	3 Levels of Delay		31		36		
t _{PLH}	Enable to Output		20		23	ns	
t _{PHL}	2 Levels of Delay		27		32		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

A, B Select. The two select inputs to the decoder.

G Enable. The enable input to the decoder. A HIGH input forces all four Y outputs HIGH regardless of the A and B inputs.

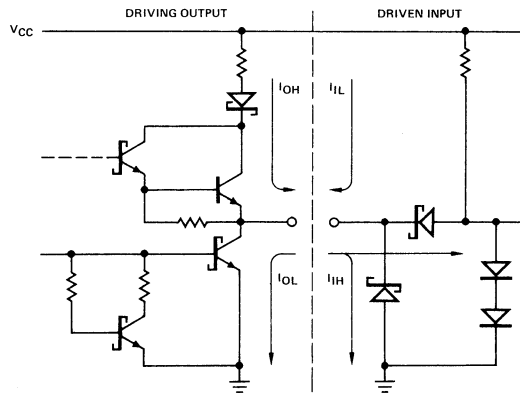
Y₀, Y₁, Y₂, Y₃ The four decoder outputs.

FUNCTION TABLE

INPUTS			OUTPUTS			
ENABLE G	SELECT B	A	Y ₀	Y ₁	Y ₂	Y ₃
H	X	X	H	H	H	H
L	L	L	L	H	H	H
L	L	H	H	L	H	H
L	H	L	H	H	L	H
L	H	H	H	H	H	L

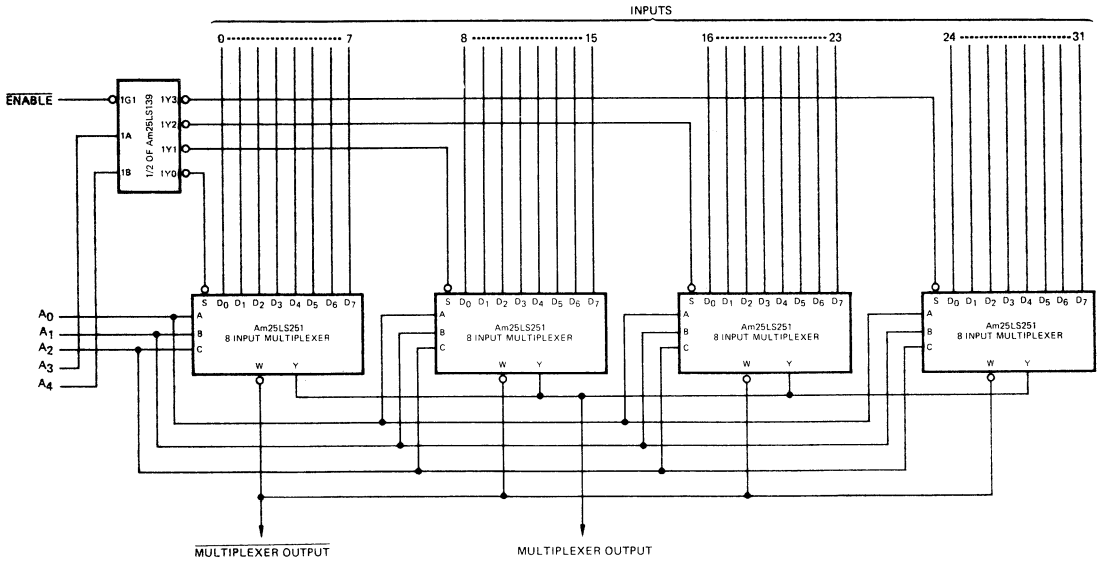
H = HIGH L = LOW X = Don't care

**Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**

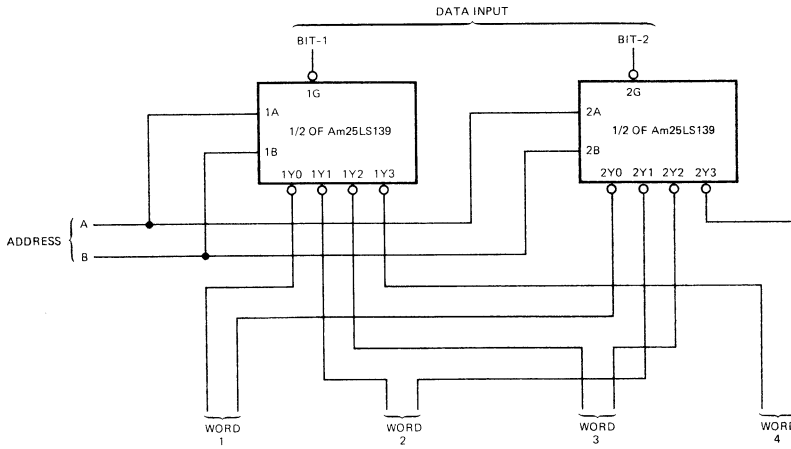


Note: Actual current flow direction shown.

APPLICATIONS

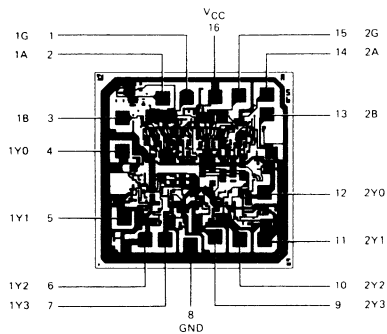


32-INPUT DEMULTIPLEXER



DATA ROUTING USING ONE Am25LS139 AS A DEMULTIPLEXER FOR TWO BITS

Metallization and Pad Layout



DIE SIZE 0.065" X 0.065"

3

Am25LS148 • Am54LS/74LS148

Eight-Line To Three-Line Priority Encoder

DISTINCTIVE CHARACTERISTICS

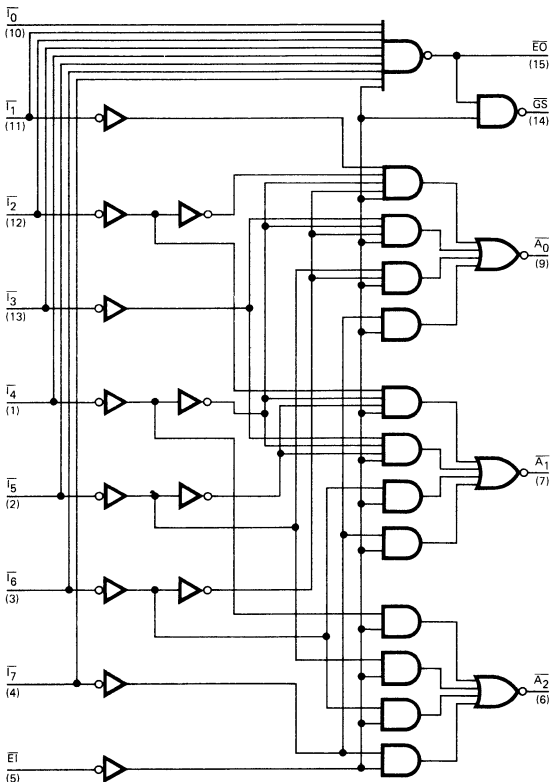
- Encodes eight inputs in priority
- Provides a 3-bit binary vector
- Indicates data present for all inputs
- Cascadable using available signals
- See Am25LS2513 for three-state output version of the Am25LS148
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL} at $I_{OL} = 8\text{mA}$
 - Twice the fan-out over military range
 - 440 μA source current at high output
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

These TTL Encoders perform priority decoding from 8 inputs and provide a binary weighted code of the priority order of the inputs on three active LOW outputs ($\overline{A}_2, \overline{A}_1, \overline{A}_0$). An active LOW enable input (\overline{EI}) and enable output (\overline{EO}) allows cascading without the need for external circuitry. Enable input \overline{EI} HIGH will force all outputs HIGH. The enable output is LOW when all inputs (I_0 to I_7) are HIGH and the enable input is LOW. A LOW group signal (\overline{GS}) indicates that one of the 8 inputs is LOW. When the enable input is LOW, the enable output is the logic inverse of the group signal.

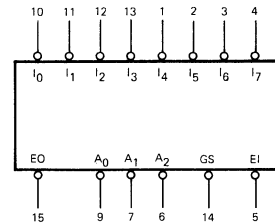
The Am54LS/74LS148 is a standard performance version of the Am25LS148. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAM



Note: The Advanced Micro Devices' LS148 products were designed prior to publication of data sheets by T.I. Review specifications for possible differences.

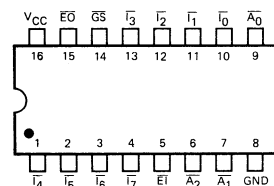
LOGIC SYMBOL



$V_{CC} = \text{Pin } 16$

$\text{GND} = \text{Pin } 8$

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

Am25LS148

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 VMIL $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$, $I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH}$ or V_{IL}	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4.0\text{mA}$			0.4	Volts
			$I_{OL} = 8.0\text{mA}$			0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$	\overline{EI} , $\overline{T_0}$			-0.4	mA
			All others			-0.8	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$	\overline{EI} , $\overline{T_0}$			20	μA
			All others			40	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 7.0\text{V}$	\overline{EI} , $\overline{T_0}$			0.1	mA
			All others			0.2	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$	Condition a		11	19	mA
			Condition b		10	16	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. a. $\overline{T_7}$, \overline{EI} Gnd all others open.b. $\overline{T_0} \rightarrow \overline{T_7}$, \overline{EI} open.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am25LS/54LS/74LS148

Am54LS/74LS148

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 V
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -400μA, V _{IN} = V _{IH} or V _{IL}	MIL	2.5	3.4	Volts
			COM'L	2.7	3.4	
V _{OL}	Output LOW Voltage	V _{CC} = MIN. V _{IN} = V _{IH} or V _{IL}	All, I _{OL} = 4.0mA		0.4	Volts
			74LS only, I _{OL} = 8.0mA		0.5	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.5	Volts
I _{IL}	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.4 V	$\overline{E}1, \overline{I}0$		-0.4	mA
			All others		-0.8	
I _{IH}	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7 V	$\overline{E}1, \overline{I}0$		20	μA
			All others		40	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 7.0 V	$\overline{E}1, \overline{I}0$		0.1	mA
			All others		0.2	
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.	-15		-100	mA
I _{CC}	Power Supply Current (Note 4)	V _{CC} = MAX.	Condition a	12	20	mA
			Condition b	10	17	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. a. $\overline{I}7, \overline{E}1$ Gnd all others open.
 b. $\overline{I}0 \rightarrow \overline{I}7, \overline{E}1$ open.

TRUTH TABLE

ENABLE IN	INPUTS								GROUP SELECT	OUTPUTS			ENABLE OUT
	$\overline{I}0$	$\overline{I}1$	$\overline{I}2$	$\overline{I}3$	$\overline{I}4$	$\overline{I}5$	$\overline{I}6$	$\overline{I}7$		GS	A ₀	A ₁	
H	X	X	X	X	X	X	X	X	H	H	H	H	H
L	H	H	H	H	H	H	H	H	H	H	H	H	L
L	X	X	X	X	X	X	X	L	L	L	L	L	H
L	X	X	X	X	X	X	L	H	L	H	L	L	H
L	X	X	X	X	X	L	H	H	L	L	H	L	H
L	X	X	X	X	L	H	H	H	L	H	H	L	H
L	X	X	X	L	H	H	H	H	L	L	L	H	H
L	X	L	H	H	H	H	H	H	L	L	H	H	H
L	L	H	H	H	H	H	H	H	L	H	H	H	H

H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Don't Care

SWITCHING CHARACTERISTICS

(T_A = +25°C, V_{CC} = 5.0V)

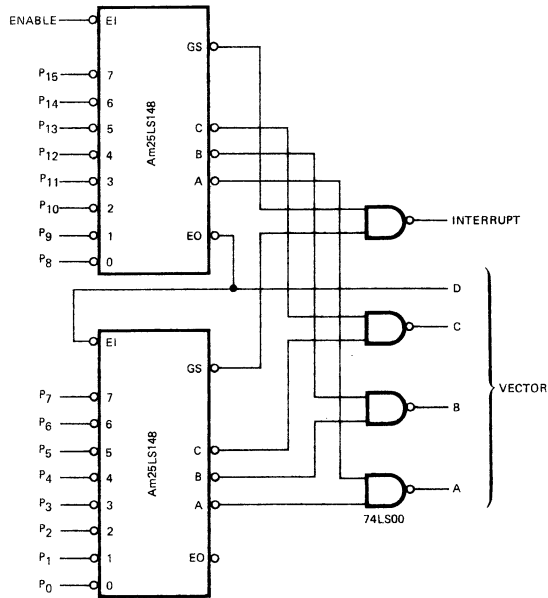
Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	\bar{I}_i to \bar{A}_n (In Phase Output)		12	18		12	18	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			9	14		17	25		
t _{PLH}	\bar{I}_i to \bar{A}_n (Out-of-Phase Output)		16	24		24	36	ns	
t _{PHL}			12	18		19	29		
t _{PLH}	\bar{I}_i to $\bar{E}O$		7	11		12	18	ns	
t _{PHL}			23	35		23	40		
t _{PLH}	\bar{I}_i to $\bar{G}S$		32	48		32	55	ns	
t _{PHL}			12	18		14	21		
t _{PLH}	$\bar{E}I$ to \bar{A}_i		13	20		13	25	ns	
t _{PHL}			8	12		17	25		
t _{PLH}	$\bar{E}I$ to $\bar{G}S$		12	17		12	17	ns	
t _{PHL}			9	14		24	36		
t _{PLH}	$\bar{E}I$ to $\bar{E}O$		9	14		14	21	ns	
t _{PHL}			25	35		25	35		

Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MiL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	\bar{I}_i to \bar{A}_n (In Phase Output)		23		27	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			21		27		
t _{PLH}	\bar{I}_i to \bar{A}_n (Out-of-Phase Output)		33		39	ns	
t _{PHL}			30		34		
t _{PLH}	\bar{I}_i to $\bar{E}O$		15		16	ns	
t _{PHL}			50		60		
t _{PLH}	\bar{I}_i to $\bar{G}S$		75		90	ns	
t _{PHL}			30		33		
t _{PLH}	$\bar{E}I$ to \bar{A}_i		28		33	ns	
t _{PHL}			21		25		
t _{PLH}	$\bar{E}I$ to $\bar{G}S$		26		30	ns	
t _{PHL}			26		30		
t _{PLH}	$\bar{E}I$ to $\bar{E}O$		19		22	ns	
t _{PHL}			60		75		

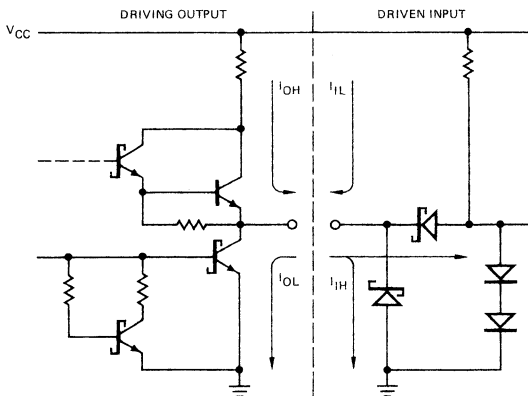
*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

APPLICATION



Priority interrupt encoding expanded to 16.

Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS

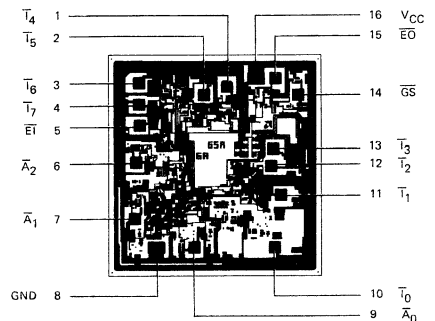


Note: Actual current flow direction shown.

DEFINITION OF FUNCTIONAL TERMS

- \bar{A}_n Address Data Outputs. Low address of most significant low data input ($n = 0, 2$).
- $\bar{E}I$ Low Enable Input. Enable input HIGH forces all outputs HIGH.
- $\bar{E}O$ Low Enable Output. Indicates that enable input is LOW and no input is active.
- $\bar{G}S$ Low Group Signal. If enable input is LOW, indicates when any input is active.
- \bar{I}_i Data Inputs. Designates one of the eight active LOW inputs ($i = 0-7$).

Metallization and Pad Layout



DIE SIZE 0.082'' X 0.085''

Am25LS151 • Am54LS/74LS151

Am25LS251 • Am54LS/74LS251

Eight-Input Multiplexers

DISTINCTIVE CHARACTERISTICS

- Switches one-of-eight inputs to two complementary outputs
- Standard, 'LS151 and three-state, 'LS251 output versions
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL}
 - Twice the fan-out over military range
 - 440 μ A source current
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

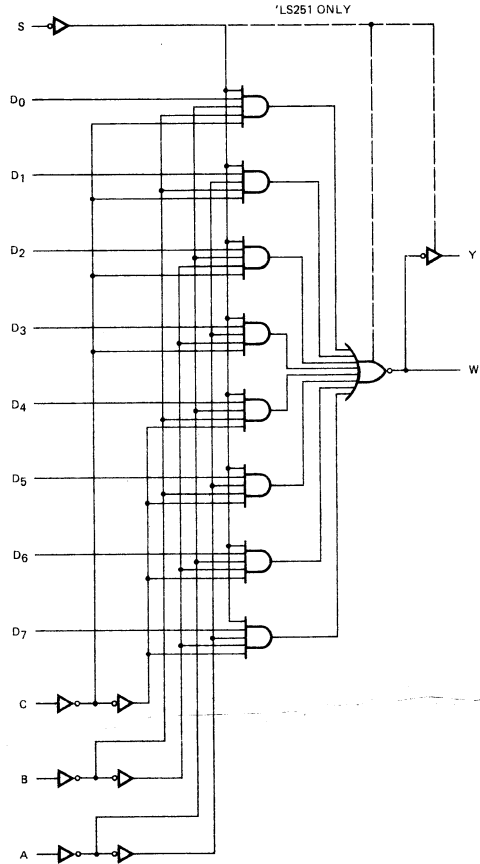
The Am25LS151 and the Am25LS251 are eight-input multiplexers that switch one of eight inputs onto the inverting and non-inverting outputs under the control of a three-bit select code. The inverting output W is one gate delay faster than the non-inverting output Y.

The Am25LS151 provides an active-LOW strobe. When the strobe is HIGH, the inverting output (W) is HIGH and the non-inverting output (Y) is LOW.

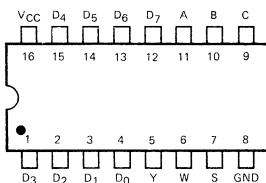
The Am25LS251 features a three-state output for data bus organization. The active-LOW strobe, or "output control" applies to both the inverting and non-inverting output. When the output control is HIGH, the outputs are in the high-impedance state. When the output control is LOW, the active pull-up output is enabled.

The Am54LS/74LS151 is a standard performance version of the Am25LS151. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAM

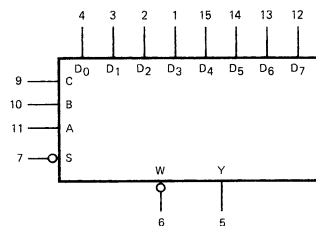


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



VCC = Pin 16
GND = Pin 8

3

Am25LS/54LS/74LS151/251

Am25LS151 • Am25LS251

ELECTRICAL CHARACTERISTICS The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	LS151XM	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -440\mu\text{A}$	2.5	3.4	Volts	
		LS151XC			2.7	3.4		
		LS251XM		$I_{OH} = -1\text{mA}$	2.4	3.4		
		LS251XC		$I_{OH} = -2.6\text{mA}$	2.4	3.2		
V_{OL}	Output LOW Voltage			$I_{OL} = 4\text{mA}$		0.4	Volts	
				$I_{OL} = 8\text{mA}$		0.45		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		MIL		0.7	Volts	
				COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$				-0.4	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$				20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$				0.1	mA	
I_{OZ}	Off-State (High-Impedance) Output Current (LS251 only)	$V_{CC} = \text{MAX.}, V_{IN} = V_{IH} \text{ or } V_{IL}$		$V_O = 2.4\text{V}$		20	μA	
				$V_O = 0.4\text{V}$		-20		
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-85	mA	
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$		LS151 (Note 4)		6.0	10	mA
				LS251 (Note 5)	A	6.1	10	
					B	7.1	12	

Am54LS/74LS151 • Am54LS/74LS251

ELECTRICAL CHARACTERISTICS The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	54LS151	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -400\mu\text{A}$	2.5	3.4	Volts	
		74LS151			2.7	3.4		
		54LS251		$I_{OH} = -1\text{mA}$	2.4	3.4		
		74LS251		$I_{OH} = -2.6\text{mA}$	2.4	3.2		
V_{OL}	Output LOW Voltage			All, $I_{OL} = 4\text{mA}$		0.4	Volts	
				74LS only, $I_{OL} = 8\text{mA}$		0.5		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		54LS		0.7	Volts	
				74LS		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$				-0.4	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$				20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$				0.1	mA	
I_{OZ}	Off-State (High-Impedance) Output Current (LS251 only)	$V_{CC} = \text{MAX.}, V_{IN} = V_{IH} \text{ or } V_{IL}$		$V_O = 2.4\text{V}$		20	μA	
				$V_O = 0.4\text{V}$		-20		
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-100	mA	
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$		LS151 (Note 4)		6.0	10	mA
				LS251 (Note 5)	A	6.1	10	
					B	7.1	12	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are $V_{CC} = 5.0\text{V}, 25^\circ\text{C}$ ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CC} is measured with all outputs open and all inputs at 4.5V.
 5. I_{CC} is measured with all outputs open and all data and select inputs at 4.5V under conditions:
 A) Strobe grounded. B) Strobe at 4.5V.

MAXIMUM RATINGS (Above which the useful life may be impaired).

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Output	30mA
DC Input Current	-30mA to +5.0mA

Am25LS151 • Am54LS/74LS151
SWITCHING CHARACTERISTICS(T_A = 25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	A, B, or C to Y; 4 Levels of Delay		27	41		27	43	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			20	30		18	30		
t _{PLH}	A, B, or C to W; 3 Levels of Delay		16	23		14	23	ns	
t _{PHL}			22	32		20	32		
t _{PLH}	Any D to Y		16	24		20	32	ns	
t _{PHL}			11	17		16	26		
t _{PLH}	Any D to W		7	12		13	21	ns	
t _{PHL}			10	15		12	20		
t _{PLH}	Strobe to Y		22	33		26	42	ns	
t _{PHL}			15	23		20	32		
t _{PLH}	Strobe to W		11	17		15	24	ns	
t _{PHL}			16	24		18	30		

3

Am25LS151 ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	A, B or C to Y; 4 Levels of Delay	T _A = 0°C to +70°C V _{CC} = 5.0V ±5%		T _A = -55°C to +125°C V _{CC} = 5.0V ±10%		ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			57		66		
t _{PLH}	A, B or C to W; 3 Levels of Delay		43		50	ns	
t _{PHL}			34		39		
t _{PLH}	Any D to Y		46		53	ns	
t _{PHL}			35		41		
t _{PLH}	Any D to W		26		30	ns	
t _{PHL}			20		23		
t _{PLH}	Strobe to Y		24		27	ns	
t _{PHL}			47		54		
t _{PLH}	Strobe to W		34		39	ns	
t _{PHL}			26		30		
t _{PLH}			35		41	ns	
t _{PHL}							

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

Am25LS/54LS/74LS151/251

Am25LS251 • Am54LS/74LS251

SWITCHING CHARACTERISTICS

(T_A = 25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	A, B, or C to Y; 4 Levels of Delay		29	44		29	45	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			20	30		28	45		
t _{PLH}	A, B, or C to W; 3 Levels of Delay		16	24		20	33	ns	
t _{PHL}			21	32		21	33		
t _{PLH}	Any D to Y		16	24		17	28	ns	
t _{PHL}			11	17		18	28		
t _{PLH}	Any D to W		8	12		10	15	ns	
t _{PHL}			9	14		9	15		
t _{ZH}	Output Enable to Y		8	12		17	45	ns	
t _{ZL}			13	19		26	40		
t _{ZH}	Output Enable to W		10	15		17	27	ns	
t _{ZL}			11	18		24	40		
t _{HZ}	Output Enable to Y		18	27		30	45	ns	
t _{LZ}			12	18		15	25		
t _{HZ}	Output Enable to W		19	29		30	55	ns	
t _{LZ}			12	18		15	25		

Am25LS251 ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	A, B or C to Y; 4 Levels of Delay	T _A = 0°C to +70°C V _{CC} = 5.0V ±5%		T _A = -55°C to +125°C V _{CC} = 5.0V ±10%		ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			61		71		
t _{PLH}	A, B or C to W; 3 Levels of Delay		43		50	ns	
t _{PHL}			35		41		
t _{PLH}	Any D to Y		46		53	ns	
t _{PHL}			35		41		
t _{PLH}	Any D to W		26		30	ns	
t _{PHL}			20		23		
t _{ZH}	Output Enable to Y		22		26	ns	
t _{ZL}			20		23		
t _{ZH}	Output Enable to W		29		33	ns	
t _{ZL}			24		27		
t _{HZ}	Output Enable to Y		24		27	ns	
t _{LZ}			27		32		
t _{HZ}	Output Enable to W		35		41	ns	
t _{LZ}			24		27		
t _{HZ}	Output Enable to W		38		44	ns	
t _{LZ}			24		27		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

FUNCTION TABLE

INPUTS					OUTPUTS			
SELECT			LS151	LS251	LS151		LS251	
C	B	A	Strobe S	Output Control S	Y	W	Y	W
X	X	X	H	H	L	H	Z	Z
L	L	L	L	L	D ₀	\bar{D}_0	D ₀	\bar{D}_0
L	L	H	L	L	D ₁	\bar{D}_1	D ₁	\bar{D}_1
L	H	L	L	L	D ₂	\bar{D}_2	D ₂	\bar{D}_2
L	H	H	L	L	D ₃	\bar{D}_3	D ₃	\bar{D}_3
H	L	L	L	L	D ₄	\bar{D}_4	D ₄	\bar{D}_4
H	L	H	L	L	D ₅	\bar{D}_5	D ₅	\bar{D}_5
H	H	L	L	L	D ₆	\bar{D}_6	D ₆	\bar{D}_6
H	H	H	L	L	D ₇	\bar{D}_7	D ₇	\bar{D}_7

H = HIGH X = Don't Care
L = LOW Z = High Impedance

D₀-D₇ = The output will follow the HIGH-level or LOW-level of the selected input.

\bar{D}_0 - \bar{D}_7 = The output will follow the complement of the HIGH-level or LOW-level of the selected input.

DEFINITION OF FUNCTIONAL TERMS

A, B, C The three select inputs of the multiplexer.

D₀, D₁, D₂, D₃,

D₄, D₅, D₆, D₇ The eight data inputs of the multiplexer.

Y The true multiplexer output.

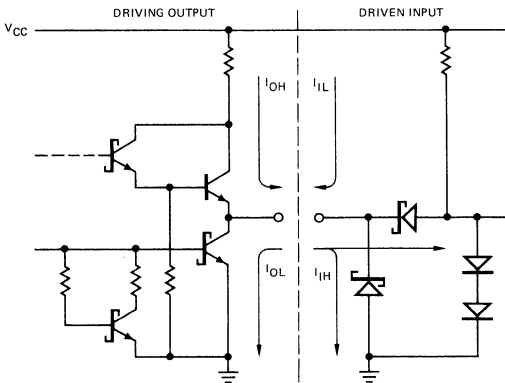
W The complement multiplexer output.

S Strobe. On the Am25LS151, a HIGH on the strobe forces the Y output LOW and the W output HIGH.

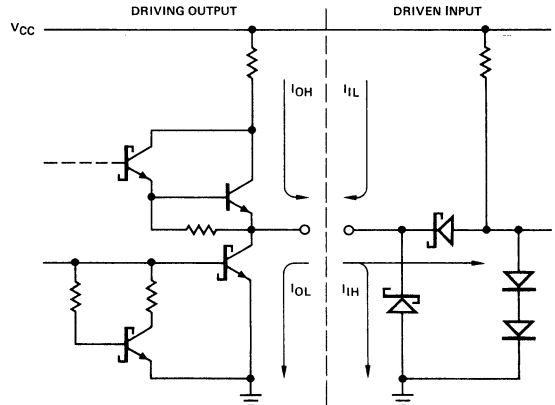
S Output Control. On the Am25LS251, a HIGH on the output control (or strobe) forces both the W and Y outputs to the high-impedance (off) state.

**Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**

**'LS251
THREE-STATE OUTPUT**



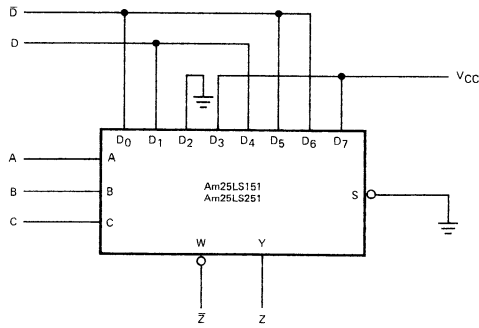
**'LS151
STANDARD OUTPUT**



Note: Actual current flow direction shown.

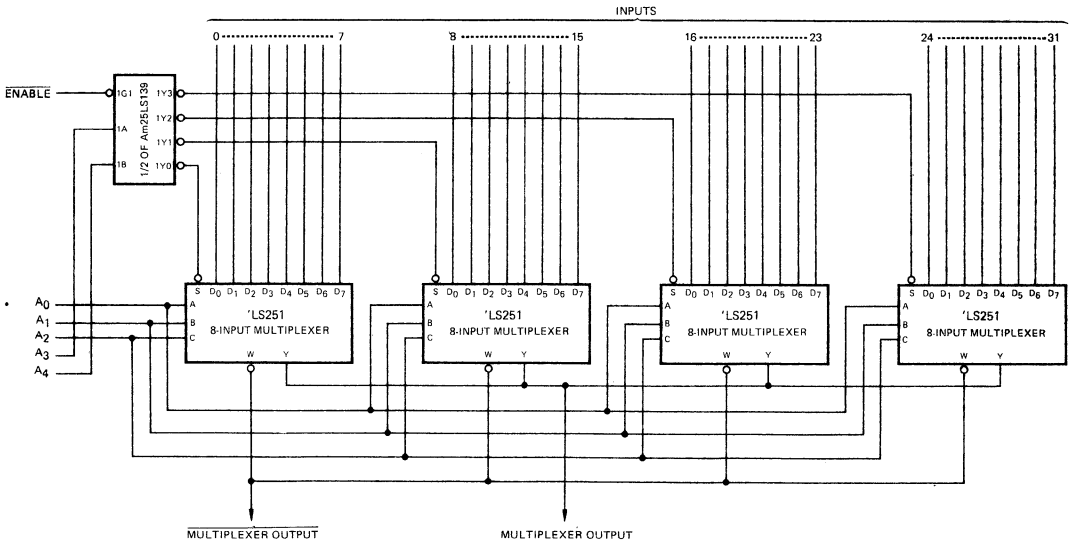
APPLICATIONS

LOGIC FUNCTION GENERATION

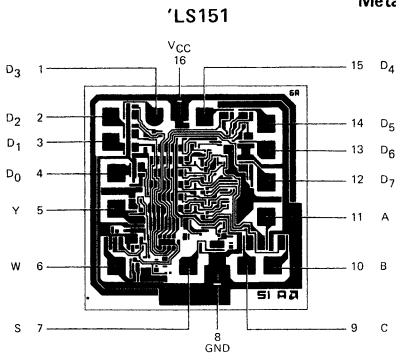


$$Z = \overline{A}BCD + \overline{A}BC\overline{D} + A\overline{C}D + AB + A\overline{C}\overline{D} + B\overline{C}\overline{D}$$

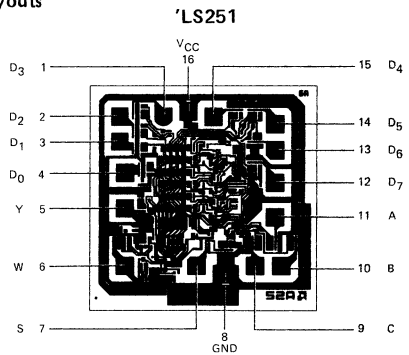
32-INPUT MULTIPLEXER



Metallization and Pad Layouts



DIE SIZE 0.057" X 0.057"



DIE SIZE 0.057" X 0.057"

Am25LS153 • Am54LS/74LS153

Am25LS253 • Am54LS/74LS253

Dual 4-Line To 1-Line Data Selectors/Multiplexers

DISTINCTIVE CHARACTERISTICS

- Performs serial to parallel conversion
- Standard, 'LS153, and three-state, 'LS253, output versions
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL}
 - Twice the fan-out over military range
 - 440 μ A source current
- 100% product assurance screening to MIL-STD-883 requirements

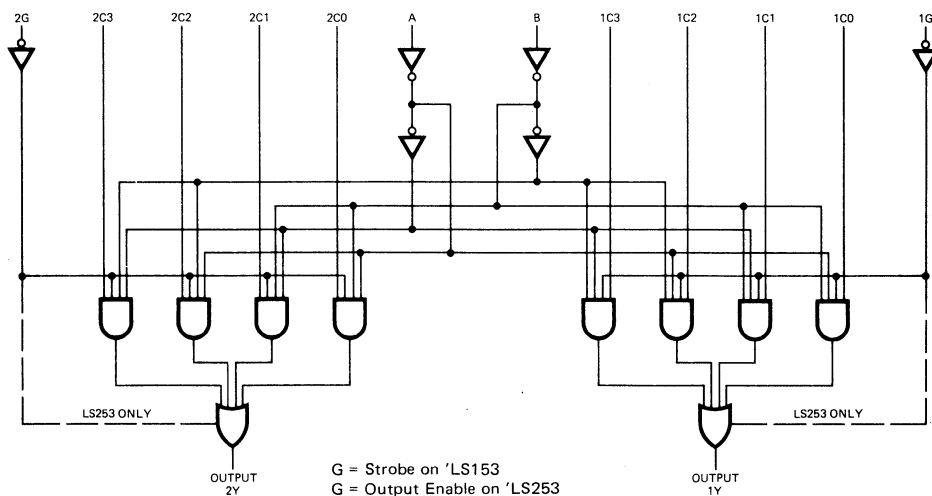
FUNCTIONAL DESCRIPTION

These dual four-input multiplexers provide the digital equivalent of a two-pole, four position switch with the position of both switches set by the logic levels supplied to the select inputs A and B. Each section of the Am25LS153 has a separate active-LOW enable (strobe) input that forces the output of that section LOW when a HIGH level is applied regardless of the other inputs.

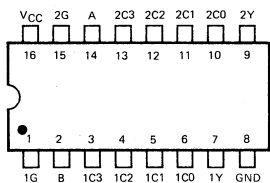
The Am25LS253 features a three-state output to interface with bus-organized systems. Each section of the Am25LS253 has a separate active-LOW output control that disables the output driver (high-impedance state) of that section when a HIGH logic level is applied regardless of the other inputs.

The Am54LS/74LS153 and 253 are standard performance versions of the Am25LS153 and 253. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAM

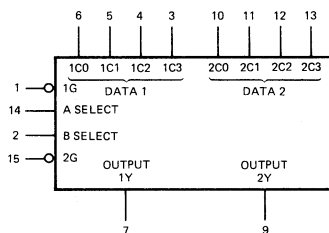


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



VCC = Pin 16
GND = Pin 8

3

Am25LS/54LS/74LS153/253

Am25LS153 • Am25LS253

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ.(Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -440\mu\text{A}$	2.5	3.4	Volts
				2.7	3.4	
				2.4	3.4	
				2.4	3.2	
V_{OL}	Output LOW Voltage		$I_{OL} = 4\text{mA}$ $I_{OL} = 8\text{mA}$		0.4	Volts
					0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL COM'L		0.7 0.8	Volts
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.36	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA
I_{OZ}	Off-State (HIGH Impedance) Output Current Am25LS253 Only	$V_{CC} = \text{MAX.}$	$V_O = 2.4\text{V}$		20	μA
			$V_O = 0.4\text{V}$		-20	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)	LS153	6.2	10	mA
			LS253	7	12	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. I_{CC} is measured with all outputs open and all inputs grounded.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

DEFINITION OF FUNCTIONAL TERMS

1C_i, 2C_i Data Inputs. The four data inputs to each multiplexer; i = 0, 1, 2, and 3.

1Y, 2Y Multiplexer Outputs. The output of each four-input multiplexer.

A, B Select Inputs. The inputs used to determine which of the four data inputs are selected for the output.

G (Am25LS153) Strobe. An active-LOW strobe used to enable the output. A HIGH level input forces the output LOW regardless of the other inputs.

G (Am25LS253) Output Control. An active-LOW three-state control used to enable the output. A HIGH level input forces the output to the high-impedance (off) state.

FUNCTION TABLE

		INPUTS					OUTPUTS		
Select		Data				LS153 Strobe	LS253 Output Control	LS153 Output	LS253 Output
B	A	C ₀	C ₁	C ₂	C ₃	G	G	Y	Y
X	X	X	X	X	X	H	H	L	Z
L	L	L	X	X	X	L	L	L	L
L	L	H	X	X	X	L	L	H	H
L	H	X	L	X	X	L	L	L	L
L	H	X	H	X	X	L	L	H	H
H	L	X	X	L	X	L	L	L	L
H	L	X	X	H	X	L	L	H	H
H	H	X	X	X	L	L	L	L	L
H	H	X	X	X	H	L	L	H	H

H = HIGH L = LOW X = Don't Care Z = High Impedance
Note: A & B are common to both 4 input multiplexers.

Am54LS/74LS153 • Am54LS/74LS253

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	54LS153	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -400\mu\text{A}$	2.5	3.4	Volts
		74LS153			2.7	3.4	
		54LS253		$I_{OH} = -1\text{mA}$	2.4	3.4	
		74LS253		$I_{OH} = -2.6\text{mA}$	2.4	3.2	
V_{OL}	Output LOW Voltage			All, $I_{OL} = 4\text{mA}$		0.4	Volts
				74LS only, $I_{OL} = 8\text{mA}$		0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		54LS		0.7	Volts
				74LS		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, V_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$				-0.36	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$				20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$				0.1	mA
I_{OZ}	Off-State (HIGH Impedance) Output Current Am54LS/74LS253 Only	$V_{CC} = \text{MAX.}$		$V_O = 2.4\text{V}$		20	μA
				$V_O = 0.4\text{V}$		-20	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-100	mA
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)		LS153		6.2	mA
				LS253		7	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. I_{CC} is measured with all outputs open and all inputs grounded.

3

Am25LS153/54LS153
SWITCHING CHARACTERISTICS $(T_A = +25^\circ\text{C}, V_{CC} = 5.0\text{V})$

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Data to Output		10	15		10	15	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			10	16		17	26		
t_{PLH}	Select to Output		19	29		19	29	ns	
t_{PHL}			15	23		25	38		
t_{PLH}	Strobe to Output		16	24		16	24	ns	
t_{PHL}			12	18		21	32		

Am25LS153 ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Data to Output		24		27	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			25		29		
t_{PLH}	Select to Output		42		48	ns	
t_{PHL}			34		39		
t_{PLH}	Strobe to Output		35		41	ns	
t_{PHL}			28		32		

*AC performance over the operating temperature range, is guaranteed by testing defined in Group A, Subgroup 9.

Am25LS/54LS/74LS153/253

Am25LS253/54LS253

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

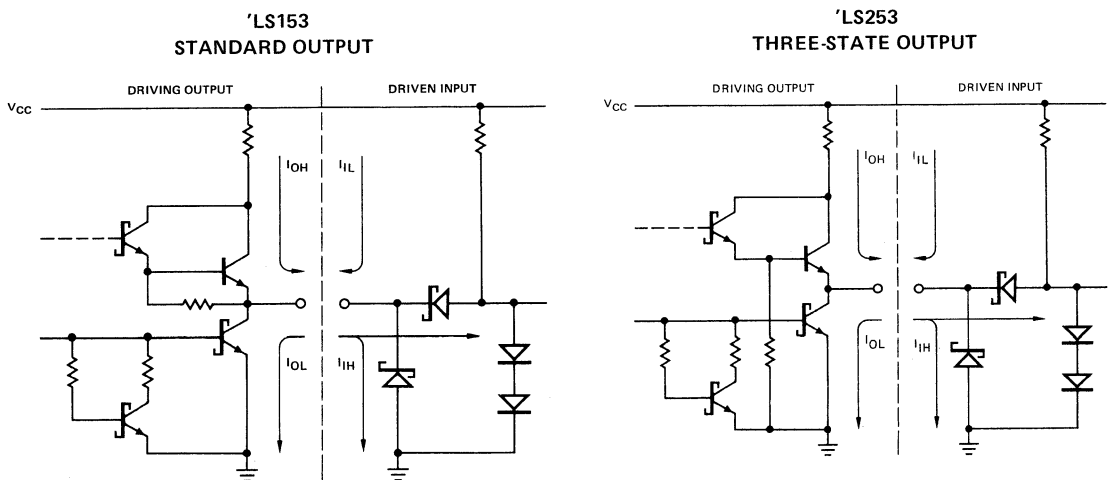
Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Data to Output		10	15		17	25	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			7	12		13	20		
t_{PLH}	Select to Output		20	30		30	45		
t_{PHL}			15	23		21	32		
t_{ZH}	Output Control to Output		17	25		15	28	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{ZL}			12	18		15	23		
t_{HZ}	Output Control to Output		12	18		27	42	ns	
t_{LZ}			13	18		18	27		

Am25LS253 ONLY SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$			
		$V_{CC} = 5.0\text{V} \pm 5\%$		$V_{CC} = 5.0\text{V} \pm 10\%$			
t_{PLH}	Data to Output		24		27	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			20		23		
t_{PLH}	Select to Output		43		50		
t_{PHL}			34		39		
t_{ZH}	Output Control to Output		37		42	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{ZL}			28		32		
t_{HZ}	Output Control to Output		28		32	ns	
t_{LZ}			28		32		

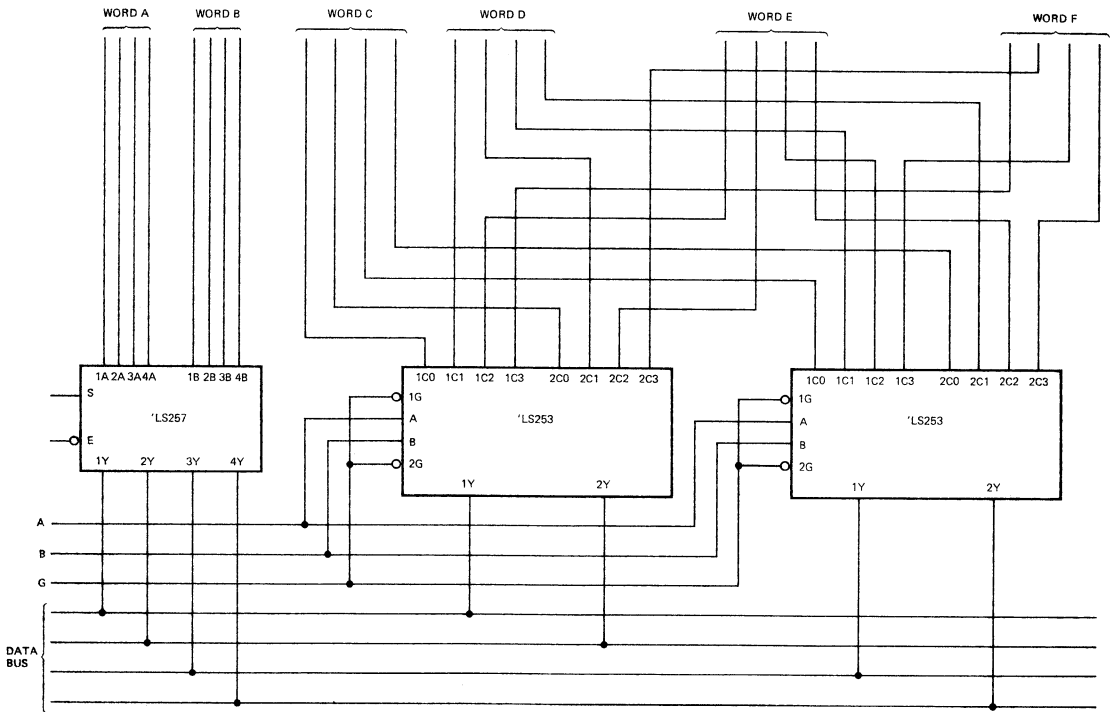
*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

Am25LS • 54LS/74LS LOW-POWER SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

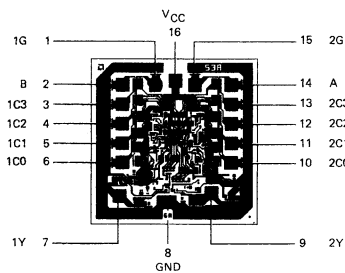
APPLICATIONS



'LS253 DUAL 4-INPUT MULTIPLEXER IN A BUS-ORGANIZED SYSTEM

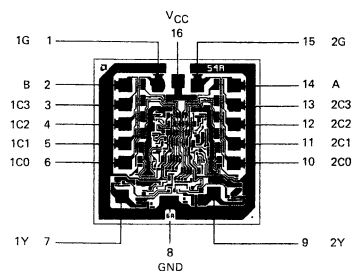
Metallization and Pad Layout

'LS153



DIE SIZE 0.055" X 0.055"

'LS253



DIE SIZE 0.055" X 0.055"

3

Am25LS157 • Am54LS/74LS157

Am25LS158 • Am54LS/74LS158

Quadruple 2-Line To 1-Line Data Selectors/Multiplexers

DISTINCTIVE CHARACTERISTICS

- Selects four of eight data inputs with single select line and overriding strobe
- Inverting 'LS158 and Non-inverting 'LS157 configurations
- Standard TTL outputs
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL}
 - Twice the fan-out over military range
 - 440 μ A source current at HIGH output
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

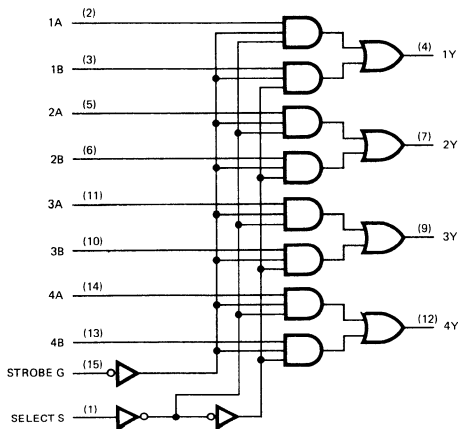
These data selectors/multiplexers are used to select a 4-bit word from one of two sources. The four outputs at the Am25LS157 present true data with respect to the input data. The four outputs of the Am25LS158 present inverted data with respect to the inputs and also minimize propagation delay. A common active-HIGH strobe (active-LOW enable) is provided on all devices.

A single select line, S, is used to select one of the two multiplexer input words. When the select is LOW, the A input word is present at the output. When the select is HIGH, the B input word is present at the output.

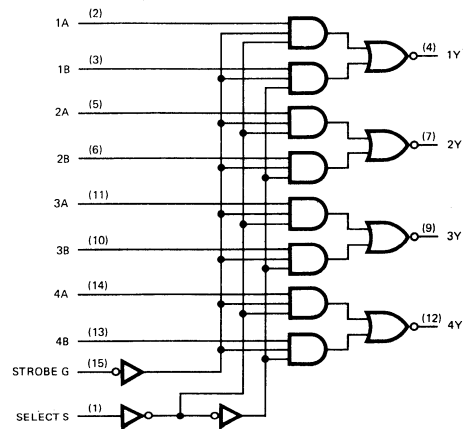
The Am54LS/74LS157 and 158 are standard performance versions of the Am25LS157 and 158. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAMS

Am25LS157
Am54LS/74LS157

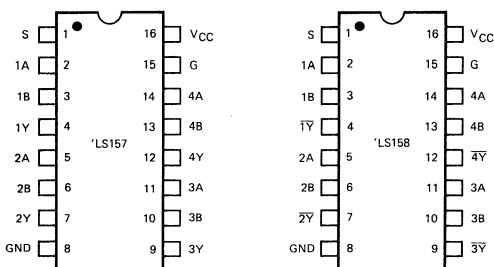


Am25LS158
Am54LS/74LS158



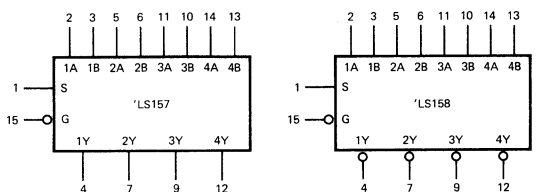
CONNECTION DIAGRAMS

Top Views



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

Am25LS157 • Am25LS158

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\%$	(MIN. = 4.75V MAX. = 5.25V)
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\%$	(MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ.(Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4\text{mA}$			0.4	Volts
			$I_{OL} = 8\text{mA}$			0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	S or G			-0.36	mA
			A or B			-0.4	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	S or G			20	μA
			A or B			20	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$	S or G			0.1	mA
			A or B			0.1	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-85	mA
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)	LS157		9.7	16	mA
			LS158		4.8	8	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CC} is measured with all outputs open and 4.5V applied to all inputs.

3

Am54LS/74LS157 • Am54LS/74LS158

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\%$	(MIN. = 4.75V MAX. = 5.25V)
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\%$	(MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ.(Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	Am54LS	2.5	3.4		Volts
			Am74LS	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	All, $I_{OL} = 4\text{mA}$			0.4	Volts
			74LS only, $I_{OL} = 8\text{mA}$			0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	Am54LS			0.7	Volts
			Am74LS			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	S or G			-0.8	mA
			A or B			-0.4	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	S or G			40	μA
			A or B			20	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$	S or G			0.2	mA
			A or B			0.1	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-100	mA
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)	LS157		9.7	16	mA
			LS158		4.8	8	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CC} is measured with all outputs open and 4.5V applied to all inputs.

Am25LS/54LS/74LS157/158

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 V to +7.0 V
DC Voltage Applied to Outputs for HIGH Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +7.0 V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am25LS157 • Am54LS/74LS157 Am25LS158 • Am54LS/74LS158

SWITCHING CHARACTERISTICS

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	Data to Output	LS157	8	12	9	14	ns	C _L = 15pF R _L = 2.0kΩ	
		LS158	5	9	7	12			
t _{PHL}	Data to Output	LS157	8	12	9	14	ns		
		LS158	7	11	7	12			
t _{PLH}	Strobe to Output	LS157	12	18	13	20	ns		
		LS158	8	12	11	17			
t _{PHL}	Strobe to Output	LS157	10	16	14	21	ns		
		LS158	11	17	12	18			
t _{PLH}	Select to Output	LS157	15	23	15	23	ns		
		LS158	13	20	13	20			
t _{PHL}	Select to Output	LS157	14	21	18	27	ns		
		LS158	14	21	16	24			

Am25LS ONLY SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	Data to Output	T _A = 0°C to +70°C V _{CC} = 5.0V ±5%		T _A = -55°C to +125°C V _{CC} = 5.0V ±10%		ns	C _L = 50pF R _L = 2.0kΩ
		LS157	20	23			
t _{PHL}	Data to Output	LS157	20	23	ns		
		LS158	16	18			
t _{PLH}	Strobe to Output	LS157	28	32	ns		
		LS158	20	23			
t _{PHL}	Strobe to Output	LS157	25	29	ns		
		LS158	26	30			
t _{PLH}	Select to Output	LS157	34	39	ns		
		LS158	30	35			
t _{PHL}	Select to Output	LS157	31	36	ns		
		LS158	31	36			

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

1A, 2A, 3A, 4A The data inputs for the 4-bits of the A word.

1B, 2B, 3B, 4B The data inputs for the 4-bits of the B word.

1Y, 2Y, 3Y, 4Y The four outputs of the multiplexer. The input data is inverted at the output on the Am25LS158 and non-inverted at the output for the Am25LS157.

G Strobe. When the strobe is HIGH, the four outputs of the Am25LS157 are LOW and the outputs of the Am25LS158 are HIGH. When the strobe is LOW, the devices are enabled to pass data.

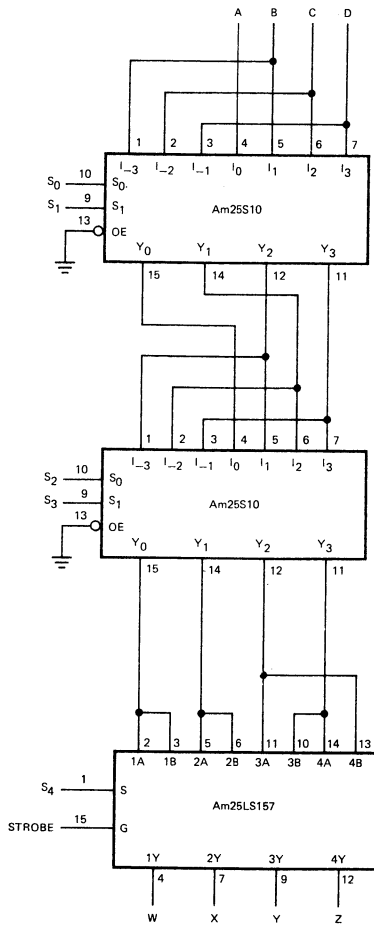
S Select. When the select input is LOW, the A word is present at the output. When the select input is HIGH, the B word is present at the output.

FUNCTION TABLE

INPUTS				OUTPUTS	
Strobe G	Select S	Data A	Data B	LS157 Y	LS158 Y
H	X	X	X	L	H
L	L	L	X	L	H
L	L	H	X	H	L
L	H	X	L	L	H
L	H	X	H	H	L

H = HIGH L = LOW X = Don't Care

APPLICATION



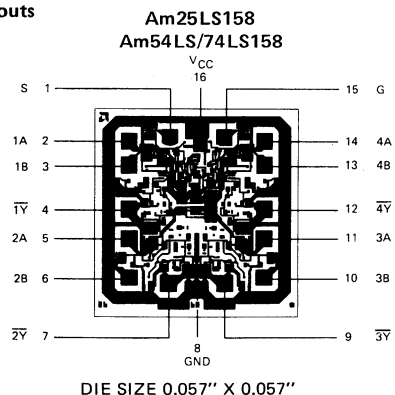
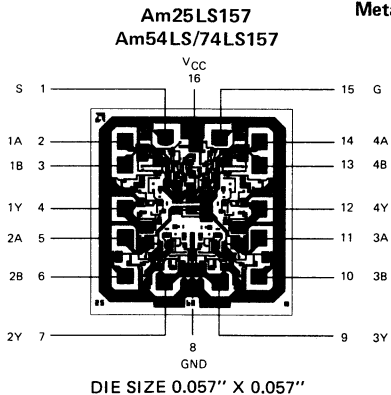
FUNCTION TABLE

State Number	Select					Output			
	S ₄	S ₃	S ₂	S ₁	S ₀	W	X	Y	Z
0	0	0	0	0	0	A	C	B	D
1	0	0	0	0	1	D	B	A	C
2	0	0	0	1	0	C	A	D	B
3	0	0	0	1	1	B	D	C	A
4	0	0	1	0	0	D	A	C	B
5	0	0	1	0	1	C	D	B	A
6	0	0	1	1	0	B	C	A	D
7	0	0	1	1	1	A	B	D	C
8	0	1	0	0	0	B	D	A	C
9	0	1	0	0	1	A	C	D	B
10	0	1	0	1	0	D	B	C	A
11	0	1	0	1	1	C	A	B	D
12	0	1	1	0	0	C	B	D	A
13	0	1	1	0	1	B	A	C	D
14	0	1	1	1	0	A	D	B	C
15	0	1	1	1	1	D	C	A	B
16	1	0	0	0	0	State 9			
17	1	0	0	0	1	State 10			
18	1	0	0	1	0	State 11			
19	1	0	0	1	1	State 8			
20	1	0	1	0	0	D	A	B	C
21	1	0	1	0	1	C	D	A	B
22	1	0	1	1	0	B	C	D	A
23	1	0	1	1	1	A	B	C	D
24	1	1	0	0	0	State 3			
25	1	1	0	0	1	State 0			
26	1	1	0	1	0	State 1			
27	1	1	0	1	1	State 2			
28	1	1	1	0	0	C	B	A	D
29	1	1	1	0	1	B	A	D	C
30	1	1	1	1	0	A	D	C	B
31	1	1	1	1	1	D	C	B	A

Two Am25S10 four-bit shifters are used in conjunction with an Am25LS157 multiplexer to perform all possible permutations on four inputs. The number of combinations possible on n items is given as n!. Thus, for n equal to 4, 24 combinations are possible. The Function Table shows all 32 combinations of the 5-bit select code including the 8 redundant states. This connection can be particularly useful in security systems and certain random number generation schemes. The eight redundant states can be placed at other select field locations through proper design.

3

Metallization and Pad Layouts



Am25LS160A/161A/162A/163A Am54LS/74LS160A/161A/162A/163A

Synchronous Four-Bit Counters

DISTINCTIVE CHARACTERISTICS

- Synchronous presettable counters
- Decade ('LS160A and 'LS162A) and binary ('LS161A and 'LS163A) counters
- Asynchronous ('LS160A and 'LS161A) and synchronous ('LS162A and 'LS163A) clear inputs
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL}
 - Twice the fan-out over military range
 - 440 μ A source current
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am25LS160A, Am25LS161A, Am25LS162A and Am25LS163A synchronous, presettable counters have internal look-ahead carry and ripple carry output for high-speed counting applications. The Am25LS160A and Am25LS162A are decade counters and the Am25LS161A and Am25LS163A are 4-bit binary counters. Counting or loading occurs on the positive transition of the clock pulse. A LOW level on the load input causes the data on the A, B, C and D inputs to be shifted to the appropriate Q outputs on the next positive clock transition. The load need meet only the set-up and hold time requirements with respect to the clock.

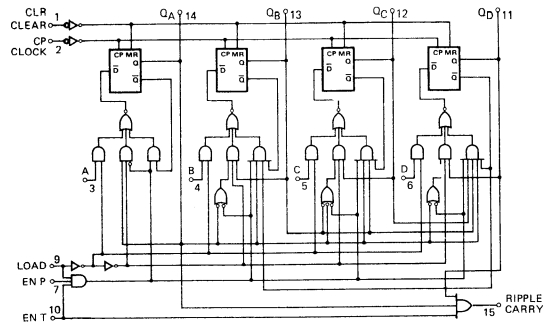
The Am25LS160A and the Am25LS161A feature an asynchronous clear. A LOW level at the clear input sets the Q outputs LOW regardless of the other inputs. The Am25LS162A and Am25LS163A have a synchronous clear. A LOW level at the clear input sets the Q outputs LOW after the next positive clock transition regardless of the enable inputs.

Both count-enable inputs P and T must be HIGH to count. Count enable T is included in the ripple carry output gate for cascading connection. The enable P or T inputs need meet only the set-up and hold time requirements with respect to the clock.

The Am54LS/74LS160A series are standard performance versions of the Am25LS160A series counters. See appropriate electrical characteristic tables for detailed Am25LS improvements.

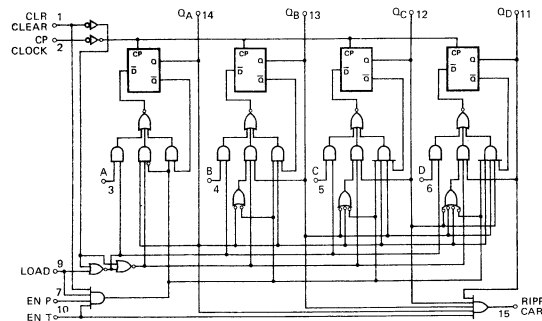
LOGIC DIAGRAMS

Am25LS160A Synchronous Decade Counter



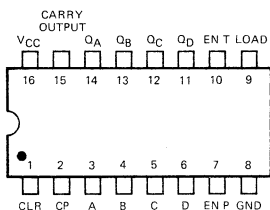
Am25LS162A synchronous decade counters are similar; however, the clear is synchronous as shown for the Am25LS163A binary counters.

Am25LS163A Synchronous Binary Counter



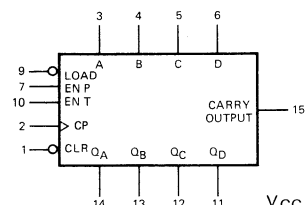
Am25LS161A synchronous binary counters are similar; however, the clear is asynchronous as shown for the Am25LS160A decade counters.

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

Am25LS160A, 161A, 162A and 163A

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\%$	(MIN. = 4.75V	MAX. = 5.25V)
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\%$	(MIN. = 4.50V	MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units		
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4	Volts		
			COM'L	2.7	3.4			
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.25	0.4	Volts	
			$I_{OL} = 8.0\text{mA}$		0.35	0.45		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts		
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts	
			COM'L					0.8
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts		
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	A, B, C, D, EN P, CP			-0.4	mA	
			Load, EN T					-0.8
			Clear '160A, '161A					-0.4
			Clear '162A, '163A					-0.4
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	A, B, C, D, EN P, CP			20	μA	
			Load, EN T					40
			Clear '160A, '161A					20
			Clear '162A, '163A					20
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$	A, B, C, D, EN P, CP			0.1	mA	
			Load, EN T					0.2
			Clear '160A, '161A					0.1
			Clear '162A, '163A					0.1
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA		
I_{CCH}	Power Supply Current All Outputs HIGH	$V_{CC} = \text{MAX.}$ (Note 4)		18	31	mA		
I_{CCL}	Power Supply Current All Outputs LOW	$V_{CC} = \text{MAX.}$ (Note 5)		19	32	mA		

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CCH} is measured with the load input HIGH, then again with the load input LOW, with all other inputs HIGH and all outputs open.
 5. I_{CCL} is measured with the clock input HIGH, then again with the clock input LOW, with all other inputs LOW and all outputs open.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

Am25LS/54LS/74LS160A/161A/162A/163A

Am54LS/74LS160A, 161A, 162A and 163A

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\%$	(MIN. = 4.75V MAX. = 5.25V)
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\%$	(MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	All, $I_{OL} = 4\text{mA}$		0.25	0.4	Volts
			74LS only, $I_{OL} = 8\text{mA}$		0.35	0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH	voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW	MIL			0.7	Volts
			COM'L				
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	A, B, C, D, EN P			-0.4	mA
			Load, EN T, CP			-0.8	
			Clear '160A, '161A			-0.4	
			Clear '162A, '163A			-0.8	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	A, B, C, D, EN P			20	μA
			Load, CP, EN T			40	
			Clear '160A, '161A			20	
			Clear '162A, '163A			40	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$	A, B, C, D, EN P			0.1	mA
			Load, CP, EN T			0.2	
			Clear '160A, '161A			0.1	
			Clear '162A, '163A			0.2	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-100	mA
I_{CCH}	Power Supply Current All Outputs HIGH	$V_{CC} = \text{MAX.}$ (Note 4)			18	31	mA
I_{CCL}	Power Supply Current All Outputs LOW	$V_{CC} = \text{MAX.}$ (Note 5)			19	32	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CCH} is measured with the load input HIGH, then again with the load input LOW, with all other inputs HIGH and all outputs open.
 5. I_{CCL} is measured with the clock input HIGH, then again with the clock input LOW, with all other inputs LOW and all outputs open.

SWITCHING CHARACTERISTICS

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	Clock to Carry Output		20	30		20	35	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			18	28		18	35		
t _{PLH}	Clock to Q Output with Load Input HIGH		10	18		13	24	ns	
t _{PHL}			12	20		18	27		
t _{PLH}	Enable T to Carry Output		8	14		9	14	ns	
t _{PHL}			8	14		9	14		
t _{PLH}	Clock to Q Output with Load Input LOW		10	18		13	24	ns	
t _{PHL}			12	20		18	27		
t _{PHL}	Clear to Q Output (Note 1)		18	28		20	28	ns	
t _{pw}	Pulse Width	Clock	25			25		ns	
		Clear	20			20			
t _s	Set-up Time	Data – A, B, C, D	20			20		ns	
		Enable P	20			20			
		Load, Enable T	20			20			
		Clear (Note 2)	20			20			
t _h	Hold Time – Any Input	3			3		ns		
f _{max} (Note 3)	Maximum Clock Frequency	35	50		25	32	MHz		

Notes: 1. Measured from clear input on 'LS160A and 'LS161A. Measured from clock input on 'LS162A and 'LS163A.

2. Applies to 'LS162A and 'LS163A only.

3. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	Clock to Carry Output		43		50	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			40		47		
t _{PLH}	Clock to Q Output with Load Input HIGH		28		32	ns	
t _{PHL}			30		35		
t _{PLH}	Enable T to Carry Output		18		21	ns	
t _{PHL}			18		21		
t _{PLH}	Clock to Q Output with Load Input LOW		28		32	ns	
t _{PHL}			30		35		
t _{PHL}	Clear to Q Output (Note 1)		41		47	ns	
t _{pw}	Pulse Width	Clock	37		42	ns	
		Clear	30		35		
t _s	Set-up Time	Data – A, B, C, D	30		35	ns	
		Enable P	30		35		
		Load, Enable T	30		35		
		Clear (Note 2)	30		35		
t _h	Hold Time – Any Input	8		9		ns	
f _{max} (Note3)	Maximum Clock Frequency	26		23		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

CP Clock pulse. Enters data or counts on the positive-going edge.

CLR Clear. On the Am25LS160A and Am25LS161A, the clear is asynchronous. A LOW on the clear sets all four flip-flops LOW. On the Am25LS162A and Am25LS163A the clear is synchronous. A LOW on the clear sets all four flip-flops LOW after the next positive-going clock edge.

Load Load. When the load is LOW, data on the A, B, C and D inputs is transferred to the output on the positive-going clock edge. When the load is HIGH, the counter is enabled.

EN P Enable P. Parallel count enable. Must be HIGH to count.

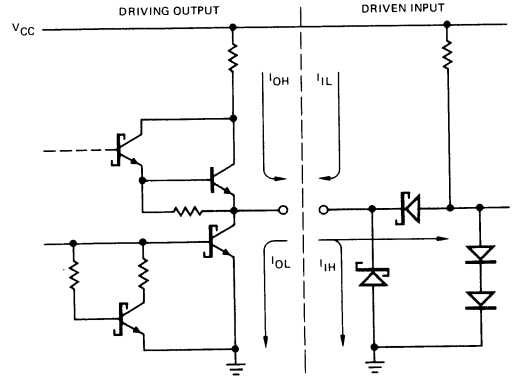
EN T Enable T. Serial trickle count enable. Must be HIGH to count.

A, B, C, D The four counter parallel inputs.

Q_A, Q_B, Q_C, Q_D The four counter outputs.

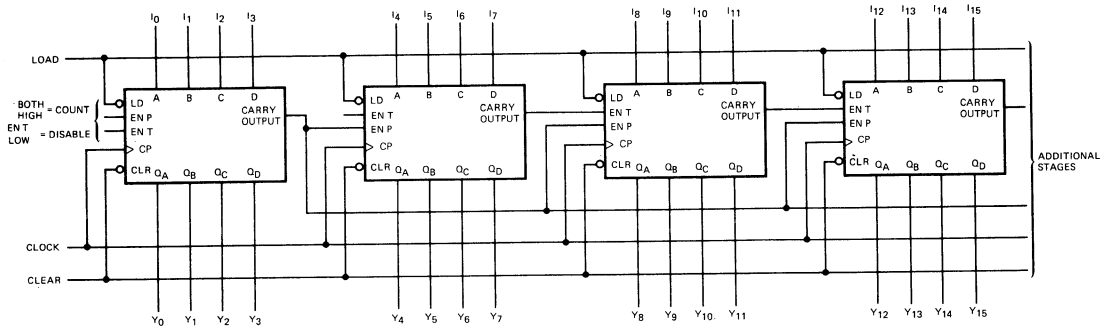
Carry Output Carry look-ahead circuitry for cascading. Will be HIGH when the four-bit counter is maximum (1001 for BCD and 1111 for binary).

**Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**



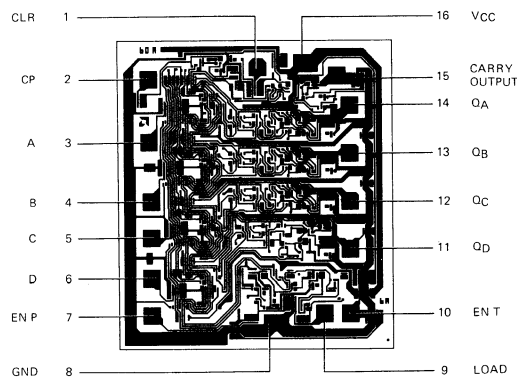
Note: Actual current flow direction shown.

APPLICATIONS



High-speed, look-ahead carry counter for BCD (Am25LS160A or Am25LS162A) or binary (Am25LS161A or Am25LS163A). Can count modulo N, N₁-to-N₂, or N₁-to-N maximum.

Metallization and Pad Layout



DIE SIZE 0.072" X 0.082"

Am25LS164 • Am54LS/74LS164

8-Bit Serial-In, Parallel-Out Shift Register

DISTINCTIVE CHARACTERISTICS

- Gated serial inputs
- Asynchronous clear
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL} at $I_{OL} = 8mA$
 - Twice the fan-out over military range
 - 440 μ A source current at HIGH output
- 100% product assurance screening to MIL-STD-883 requirements

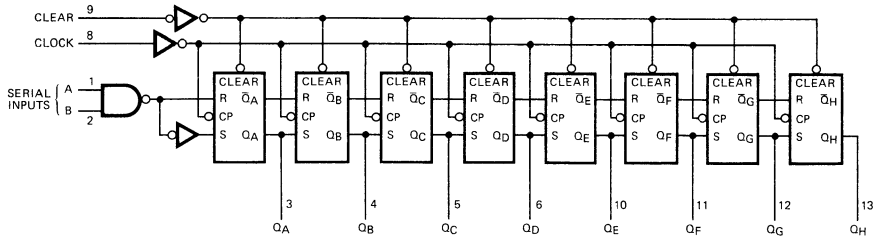
FUNCTIONAL DESCRIPTION

The Am25LS164 and Am54LS/74LS164 are eight-bit, serial in/parallel out shift registers built using advanced Low-Power Schottky processing. A gated input provides enable/disable control over incoming data such that the data can be entered or logic zeros can be entered into the register.

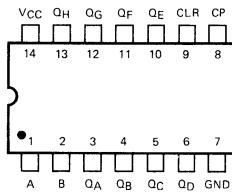
An asynchronous clear input can be used to simultaneously clear the eight flip-flops in the device. When the clear input is LOW, all internal flip-flops are forced LOW independent of the clock input. An incoming data bit is entered into the Q_A flip-flop and the data in all internal flip-flops is shifted right on the LOW-to-HIGH transition of the clock input.

The Am54LS/74LS164 is a standard performance version of the Am25LS164. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAM

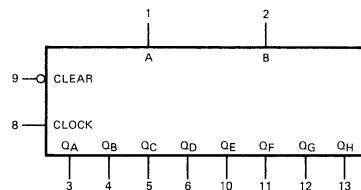


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 14

GND = Pin 7

3

Am25LS/54LS/74LS164

Am25LS164

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{ V} \pm 5\%$	MIN. = 4.75 V	MAX. = 5.25 V
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{ V} \pm 10\%$	MIN. = 4.50 V	MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\ \mu\text{A}$ $V_{IN} = V_{IH}$ or V_{IL}	MIL	2.5	3.4	Volts	
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4.0\text{ mA}$		0.25	0.4	Volts
			$I_{OL} = 8.0\text{ mA}$		0.35	0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L				
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{ mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{ V}$	Clock, Clear			-0.36	mA
			A, B				
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{ V}$			20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{ V}$			0.1	mA	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		16	27	mA	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{ V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Measured with outputs open, serial inputs grounded, and a momentary ground, then 4.5V applied to the clear input.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

DEFINITION OF FUNCTIONAL TERMS

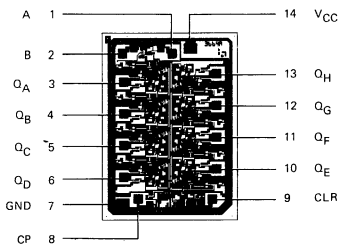
A, B The serial inputs to the device. If either the A input is LOW or the B input is LOW, the Q_A flip-flop will be set LOW on the LOW-to-HIGH transition of the clock.

Clear An asynchronous master reset for the eight flip-flops in the device. When the clear input is LOW, all internal flip-flops are set LOW independent of the clock.

Q_A-Q_H The eight true outputs of the eight-bit register.

Clock The clock input to the register. Data is entered into the register on the LOW-to-HIGH transition of the clock input.

Metallization and Pad Layout



DIE SIZE 0.066" X 0.090"

Am54LS/74LS164

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 V
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\ \mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4	Volts	
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	All, $I_{OL} = 4.0\text{mA}$		0.25	0.4	Volts
			74LS only, $I_{OL} = 8.0\text{mA}$		0.35	0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L				
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.4	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-100	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		16	27	mA	

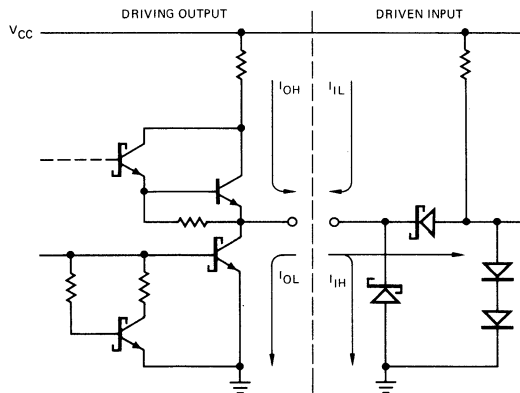
Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. Measured with outputs open, serial inputs grounded, and a momentary ground, then 4.5V applied to the clear input.

Am25LS • Am54LS/74LS
 LOW POWER SCHOTTKY INPUT/OUTPUT
 CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

Am25LS/54LS/74LS164

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	Clock to Output		14	20		17	27	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			15	22		21	32		
t _{PHL}	Clear to Output		19	29		24	36		
t _{pw}	Clock or Clear	17			20				
t _s	Data	10			15				
t _h	Data	5.0			5.0				
t _s	Clear Recovery Time	20			—	—			
f _{max} (Note 1)	Maximum Clock Frequency	35	42		25	36			

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

Am25LS ONLY SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	Clock to Output		26		30	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			30		35		
t _{PHL}	Clear to Output		37		42		
t _{pw}	Clock or Clear	22		25			
t _s	Data	13		15			
t _h	Data	5		5			
t _s	Clear Recovery Time	25		30			
f _{max} (Note 1)	Maximum Clock Frequency	25		20			

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

TRUTH TABLE

Function	Clear	Clock	Serial		Q _A	Q _B	Q _C	Q _D	Q _E	Q _F	Q _G	Q _H
			A	B								
Clear	L	X	X	X	L	L	L	L	L	L	L	L
Shift Right	H	↑	L	L	L	Q _A	Q _B	Q _C	Q _D	Q _E	Q _F	Q _G
	H	↑	L	H	L	Q _A	Q _B	Q _C	Q _D	Q _E	Q _F	Q _G
	H	↑	H	L	L	Q _A	Q _B	Q _C	Q _D	Q _E	Q _F	Q _G
	H	↑	H	H	H	Q _A	Q _B	Q _C	Q _D	Q _E	Q _F	Q _G

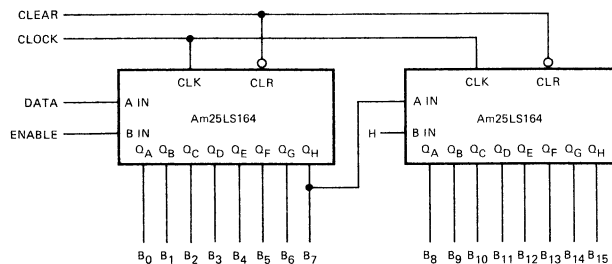
L = LOW
H = HIGH

↑ = LOW-to-HIGH transition
X = Don't care

ORDERING INFORMATION

Package Type	Temperature Range	Am25LS164 Order Number	SN54/74LS164 Order Number
Molded DIP	0°C to +70°C	AM25LS164PC	SN74LS164N
Hermetic DIP	0°C to +70°C	AM25LS164DC	SN74LS164J
Dice	0°C to +70°C	AM25LS164XC	SN74LS164X
Hermetic DIP	-55°C to +125°C	AM25LS164DM	SN54LS164J
Hermetic Flat Pak	-55°C to +125°C	AM25LS164FM	SN54LS164W
Dice	-55°C to +125°C	AM25LS164XM	SN54LS164X

APPLICATION



16-Bit Serial In Parallel Out Register.

Am25LS168A • Am25LS169A Am54LS/74LS168A • Am54LS/74LS169A

Synchronous Four-Bit Programmable Up-Down Counter

DISTINCTIVE CHARACTERISTICS

- All operations are synchronous
- Internal look-ahead carry logic for high-speed counting
- Ripple carry output provided for cascading
- One line up/down control
- Changes state on LOW-to-HIGH transition of clock
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL} at $I_{OL} = 8mA$
 - Twice the fan-out over military range
 - 440 μA source current at HIGH output
- 100% product assurance screening to MIL-STD-883 requirements

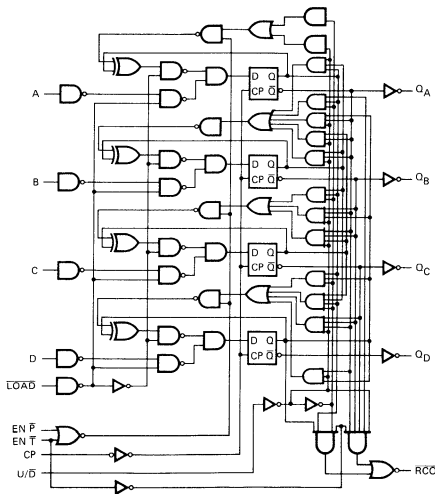
FUNCTIONAL DESCRIPTION

The 'LS168A and 'LS169A are fully synchronous programmable up/down counters. All operations occur on the positive edge of the clock input. Proper operation only requires the user to meet the set-up and hold times. With the LOAD input LOW the outputs will be programmed by the parallel data inputs on the LOW-to-HIGH transition of the clock. Counting is enabled only when $\overline{EN\ T}$ and $\overline{EN\ P}$ are LOW. The up/down inputs (U/\overline{D}) control of the direction of the count. HIGH counts up and LOW counts down. Internal Look-Ahead Carry logic and active LOW ripple carry output (\overline{RCO}) allows for high-speed counting and cascading. During up count, the \overline{RCO} is LOW at binary 9 for the 'LS168A (binary 15 for the 'LS169A) and upon down count, it is LOW at binary 0 (same for the 'LS169A). Cascaded operation requires only the \overline{RCO} to be connected to the succeeding block at $\overline{EN\ T}$.

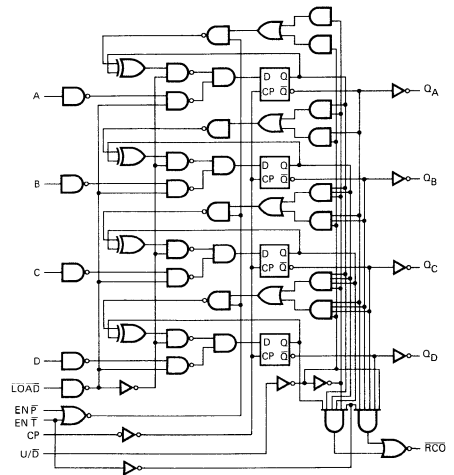
The Am54LS/74LS168A and 169A are standard performance versions of the Am25LS168A and 169A. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAMS

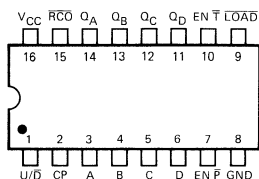
'LS168A



'LS169A

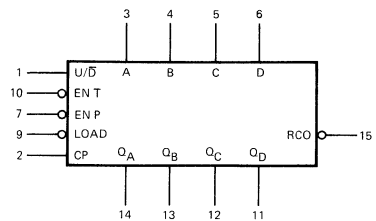


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

Am25LS168A • Am25LS169A

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25V
 MIL $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$, $I_{OH} = -440\mu\text{A}$, $V_{IN} = V_{IH}$ or V_{IL}	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$, $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4.0\text{mA}$			0.4	Volts
			$I_{OL} = 8.0\text{mA}$			0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$	EN \bar{T}			-0.6	mA
			All others			-0.4	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$	EN \bar{T}			30	μA
			All others			20	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 7.0\text{V}$	EN \bar{T}			0.15	mA
			All others			0.1	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		20	34	mA	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. All inputs grounded; outputs open; measured after a ground then 4.5V on the clock input.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to $+V_{CC}$ max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am25LS/54LS/74LS168A/169A

Am54LS/74LS168A • Am54LS/74LS169A

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25V

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}, V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4	Volts
			COM'L	2.7	3.4	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}, V_{IN} = V_{IH} \text{ or } V_{IL}$	All, $I_{OL} = 4.0\text{mA}$		0.4	Volts
			74LS only, $I_{OL} = 8.0\text{mA}$		0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	EN \bar{T}		-0.6	mA
			All others		-0.4	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	EN \bar{T}		30	μA
			All others		20	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$	EN \bar{T}		0.15	mA
			All others		0.1	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-100	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		20	34	mA

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. All inputs grounded; outputs open; measured after a ground then 4.5 V on the clock input.

FUNCTION TABLE

INPUTS									OUTPUTS				COMMENTS	
CP	A	B	C	D	LOAD	EN \bar{T}	EN \bar{P}	U/ \bar{D}	\bar{RCO}	Q_A	Q_B	Q_C		Q_D
↑	X	X	X	X	H	L	L	H	A/R(1)	$(Q_{T-CK}) + 1$				Count Up
↑	X	X	X	X	H	L	L	L	A/R(2)	$(Q_{T-CK}) - 1$				Count Down
↑	X	X	X	X	H	H	X	X	NC	NC				Count Inhibit
↑	X	X	X	X	H	X	H	X	NC	NC				
NC	X	X	X	X	H	L	X	H	L	H	H	H	H	Overflow ('LS169A) ('LS168A)
NC	X	X	X	X	H	L	X	H	L	(H	X	X	H)	
NC	X	X	X	X	H	H	X	H	H	H	X	H	H	Overflow Inhibit ('LS169A) ('LS168A)
NC	X	X	X	X	H	H	X	H	H	(H	X	X	H)	
NC	X	X	X	X	H	L	X	L	L	L	L	L	L	Underflow
NC	X	X	X	X	H	H	X	L	H	L	L	L	L	Underflow Inhibit
↑	L	H	L	H	L	L	L	X	H	L	H	L	H	Load Example

Notes: 1. LOW for one clock cycle when maximum count is reached; otherwise HIGH.

2. LOW for one clock cycle when minimum count is reached; otherwise HIGH.

H = HIGH

L = LOW

X = Don't Care

(Q_{T-CK}) = Output State Prior to Clock Edge.

A/R = Assumes Required State at Output.

NC = No Change.

SWITCHING CHARACTERISTICS(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	Clock to Ripple Carry		23	35		23	35	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			19	35		23	35		
t _{PLH}	Clock to Any Q		13	20		13	20	ns	
t _{PHL}			15	23		15	23		
t _{PLH}	Enable \bar{T} to Ripple Carry		10	14		10	14	ns	
t _{PHL}			9	14		10	14		
t _{PLH}	Up/Down to Ripple Carry		17	25		17	25	ns	
t _{PHL}			17	29		19	29		
t _{pw}	Clock Pulse Width	25			25			ns	
t _s	Set-up	A, B, C, D	20		20			ns	
		EN \bar{P} , EN \bar{T}	20		20				
		Load	25		25			ns	
		Up/Down	30		30				
t _h	Hold, any Input	0			0			ns	
f _{max} (Note 1)	Maximum Clock Frequency	25	2		25	32		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

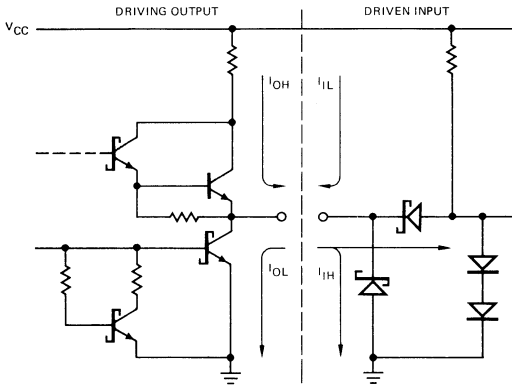
3

Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	Clock to Ripple Carry		49		57	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			49		57		
t _{PLH}	Clock to Any Q		30		35	ns	
t _{PHL}			34		39		
t _{PLH}	Enable \bar{T} to Ripple Carry		22		26	ns	
t _{PHL}			22		26		
t _{PLH}	Up/Down to Ripple Carry		36		42	ns	
t _{PHL}			42		48		
t _{pw}	Clock Pulse Width	36		42		ns	
t _s	Set-Up	A, B, C, D	30		35	ns	
		EN \bar{T} , EN \bar{P}	30		35		
		Load	36		42	ns	
		Up/Down	43		50		
t _h	Hold	0		0		ns	
f _{max} (Note 1)	Maximum Clock Frequency	19		17		MHz	

*AC performance over operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

**Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**



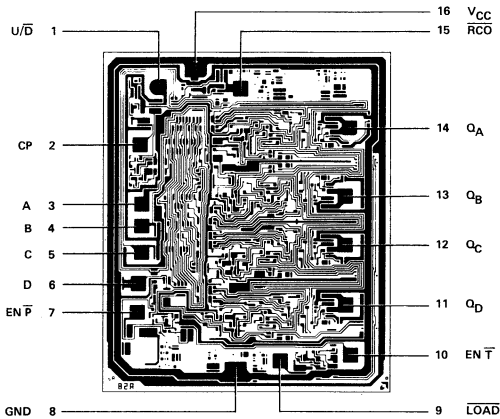
Note: Actual current flow direction shown.

DEFINITION OF FUNCTIONAL TERMS

- CP** Clock Pulse. All functions of the counter occurs on the positive edge.
- A, B, C, D** The four programmable data inputs.
- EN \bar{P}** Parallel Count Enable. Must be LOW to count.
- EN \bar{T}** Enables RCO (serial trickle) for cascading counters. Must be LOW to count.
- Q_A, Q_B, Q_C, Q_D** The four counter outputs.
- LOAD** A LOW enables parallel load of counter outputs from inputs. Must be HIGH to count.
- \bar{RCO}** Ripple Carry Output. Output will be LOW on the maximum count on up count, and on 0000 on the down count.
- U/ \bar{D}** Up/Down Count Control. HIGH counts up and LOW counts down.

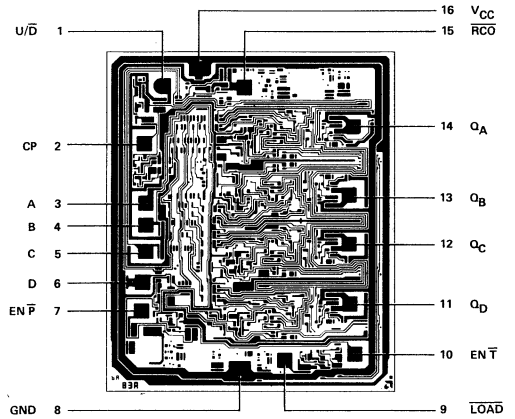
Metallization and Pad Layouts

'LS168A



DIE SIZE 0.084" X 0.099"

'LS169A

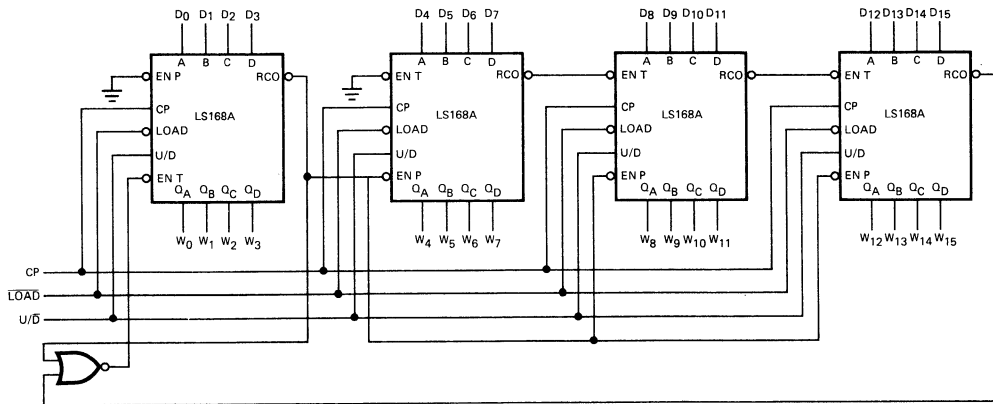


DIE SIZE 0.084" X 0.099"

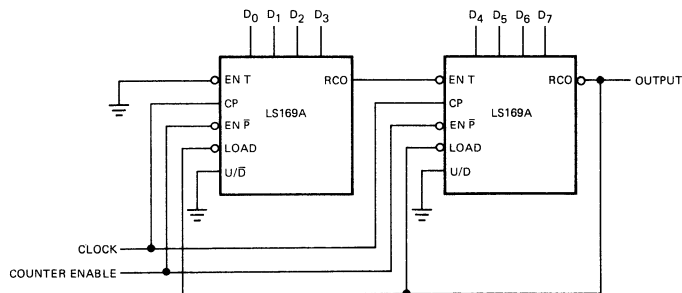
ORDERING INFORMATION

Package Type	Temperature Range	Am25LS168A Order Number	Am25LS169A Order Number	Am54LS/74LS168A Order Number	Am54LS/74LS169A Order Number
Molded DIP	0°C to +70°C	AM25LS168APC	AM25LS169APC	SN74LS168AN	SN74LS169AN
Hermetic DIP	0°C to +70°C	AM25LS168ADC	AM25LS169ADC	SN74LS168AJ	SN74LS169AJ
Dice	0°C to +70°C	AM25LS168AXC	AM25LS169AXC	SN74LS168AX	SN74LS169AX
Hermetic DIP	-55°C to +125°C	AM25LS168ADM	AM25LS169ADM	SN54LS168AJ	SN54LS169AJ
Hermetic Flat Pak	-55°C to +125°C	AM25LS168AFM	AM25LS169AFM	SN54LS168AW	SN54LS169AW
Dice	-55°C to +125°C	AM25LS168AXM	AM25LS169AXM	SN54LS168AX	SN54LS169AX

APPLICATIONS



Synchronous 4-Bit BCD Programmable Up/Down Counter with Hold on Underflow and Overflow, enabled by $\overline{\text{LOAD}}$, Single count sequence per load cycle.



Programmable Divide By N.

Example: Divide By 127, Load (N-1) or 126 = 01111110.

Am25LS170·Am25LS670 Am54LS/74LS170·Am54LS/74LS670

4-BY-4 Register File with 3-State or Open Collector Outputs

DISTINCTIVE CHARACTERISTICS

- Separate read/write addressing
- Simultaneous read and write
- 4-word by 4-bit organization
- Am25LS170 has open collector outputs
- Am25LS670 has three-state outputs
- Cascadable to m words of n bits (Mod 4)
- Used as
 - Scratchpad memory
 - Buffer storage with timing synchronizing
 - Storage for fast multiply (signal processing)
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL} at $I_{OL} = 8\text{mA}$
 - Twice the fan-out over military range
 - 440 μA source current at HIGH output
- 100% product assurance screening to MIL-STD-883 requirements

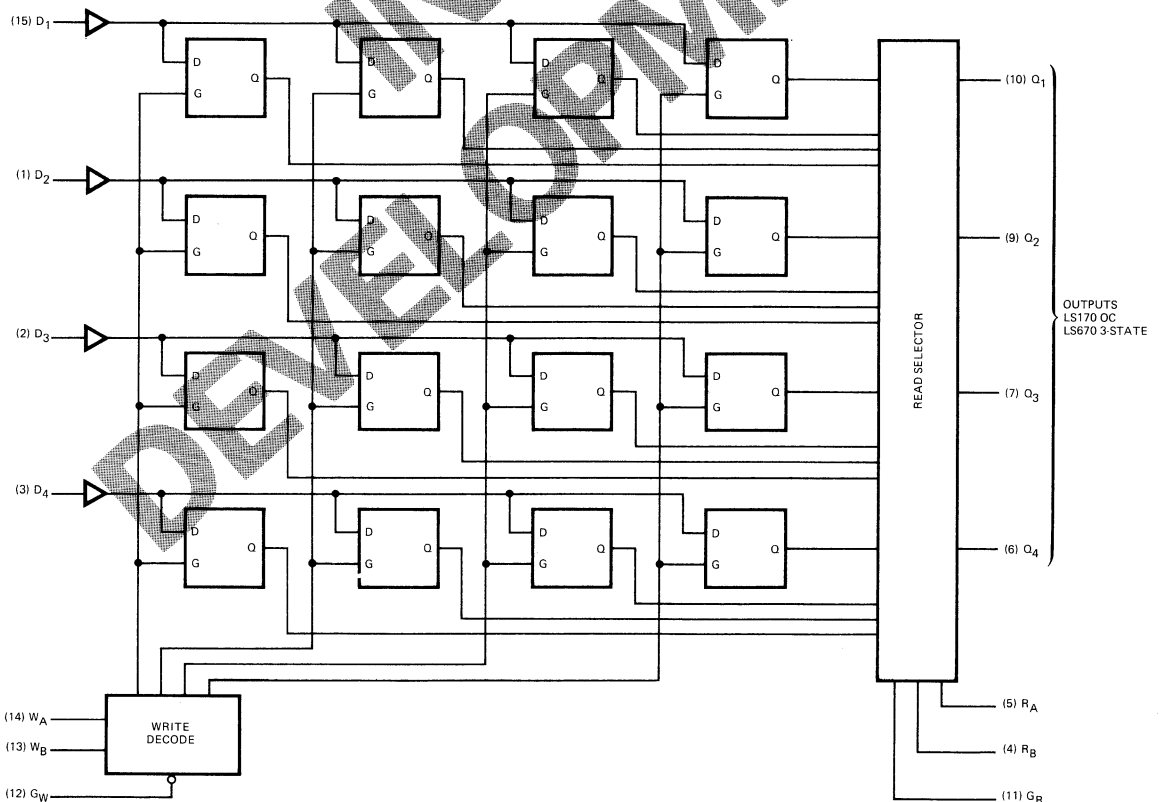
FUNCTIONAL DESCRIPTION

The Am25LS170 and 670 are 16-bit low-power Schottky register files. The file is organized as 4 words of 4-bits each with separate on-chip address decoding for read and write. This permits simultaneous read and write operations either to the same or different addresses.

Four data inputs are used to supply the 4-bit data word to be stored. The W_A and W_B inputs supply the write address while the G_W supplies the write enable. Four data outputs (O_0 to O_3) are selected from data word cells by the R_A and R_B address. The output is available if the read enable G_R is LOW. The register file performs a non-destructive readout. The Am25LS170 has open collector output for convenience of collector ORing while the Am25LS670 provides three-state outputs for bus selection.

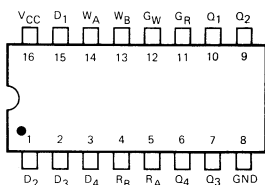
The Am54LS/74LS170 and 670 are standard performance versions of the Am25LS160 and 670. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAM



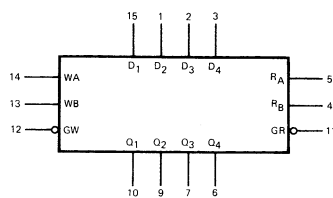
CONNECTION DIAGRAM

Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



$V_{CC} = 16$
 $GND = 8$

Am25LS170 • Am25LS670

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V, MAX. = 5.25V)

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V, MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units		
V_{OH}	Output HIGH Voltage (LS670 Only)	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	MIL, $I_{OH} = -1.0\text{mA}$	2.4		Volts		
			COM'L, $I_{OH} = -2.6\text{mA}$	2.4				
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4.0\text{mA}$		0.25	0.4	Volts	
			$I_{OL} = 8.0\text{mA}$		0.35	0.45		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts		
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts	
			COM'L					0.8
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$				-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$	Any D, R, or W			-0.36	mA	
			GR (LS170) or GW					-0.72
			GR (LS670)					-1.08
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$	Any D, R, or W			20	μA	
			GR (LS170) or GW					40
			GR (LS670)					60
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 7.0\text{V}$	Any D, R, or W			0.1	mA	
			GR (LS170) or GW					0.2
			GR (LS670)					0.3
I_{OH}	Output Leakage (LS170 Only)	$V_{CC} = \text{MIN.}$, $V_{OH} = 5.5\text{V}$, $V_{IN} = V_{IH}$ or V_{IL}				20	μA	
I_{OZ}	Off-State (High-Impedance) Output Current (LS670 Only)	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$			-20	μA	
			$V_O = 2.7\text{V}$					20
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-85	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$	170		25	40	mA	
			670		30	50		

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. Measured with 4.5V applied to all data inputs and both enable inputs, all address inputs grounded and all outputs open.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am54LS/74LS170 • Am54LS/74LS670

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V, MAX. = 5.25V)
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V, MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage (LS670 Only)	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL, $I_{OH} = -1.0\text{mA}$	2.4	3.4	Volts
			COM'L, $I_{OH} = -2.6\text{mA}$	2.4	3.4	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	All, $I_{OL} = 4.0\text{mA}$			0.4
			74LS Only, $I_{OL} = 8.0\text{mA}$			0.5
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0		Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7
			COM'L			0.8
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$				-1.5
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$	Any D, R, or W			-0.4
			GR (LS170) or GW			-0.8
			GR (LS670)			-1.2
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$	Any D, R, or W			20
			GR (LS170) or GW			40
			GR (LS670)			60
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 7.0\text{V}$	Any D, R, or W			0.1
			GR (LS170) or GW			0.2
			GR (LS670)			0.3
I_{OH}	Output Leakage (LS170 Only)	$V_{CC} = \text{MIN.}$, $V_{OH} = 5.5\text{V}$, $V_{IN} = V_{IH} \text{ or } V_{IL}$				20
I_{OZ}	Off-State (High-Impedance) Output Current (LS670 Only)	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$			-20
			$V_O = 2.7\text{V}$			20
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-100
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$	170		25	40
			670		30	50

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Measured with 4.5V applied to all data inputs and both enable inputs, all address inputs grounded and all outputs open.

DEFINITION OF FUNCTIONAL TERMS

- D₁ – D₄** Data Input. Input data bit 1 through bit 4 representing one word to be entered into the device.
RA RB Read Word Select. Selects word 0 through word 3 to be read out.
GR Read Enable. Gates output of LS170 and enables three-state output on LS670.;
WA WB Write Word Select. Selects which word is to be written.
GW Write Enable. The selected word will be written when the G_W goes LOW.
Q₁ – Q₄ Output data bits 1 through 4 available during read select (G_R) otherwise HIGH for LS170 (open collector) or high impedance for LS670 (three-state).

TRUTH TABLE

WRITE INPUTS			WORD			
W_B	W_A	G_W	0	1	2	3
L	L	L	Q=D	NC	NC	NC
L	H	L	NC	Q=D	NC	NC
H	L	L	NC	NC	Q=D	NC
H	H	L	NC	NC	NC	Q=D
X	X	H	NC	NC	NC	NC

READ INPUTS			OUTPUTS			
R_B	R_A	G_R	Q ₁	Q ₂	Q ₃	Q ₄
L	L	L	W ₀ B ₀	W ₀ B ₁	W ₀ B ₂	W ₀ B ₃
L	H	L	W ₁ B ₀	W ₁ B ₁	W ₁ B ₂	W ₁ B ₃
H	L	L	W ₂ B ₀	W ₂ B ₁	W ₂ B ₂	W ₂ B ₃
H	H	L	W ₃ B ₀	W ₃ B ₁	W ₃ B ₂	W ₃ B ₃
LS170 Only:						
X	X	H	H	H	H	H
LS670 Only:						
X	X	H	Z	Z	Z	Z

- Notes: 1. H = HIGH level, L = LOW level, X = Don't Care, Z = HIGH impedance.
 2. (Q=D) the selected F/F will assume the state of D_{in} .
 3. NC = the level of Q previously established (no change).
 4. $W_i B_j = i$ = the word read,
 j = the bit read.

SWITCHING CHARACTERISTICS

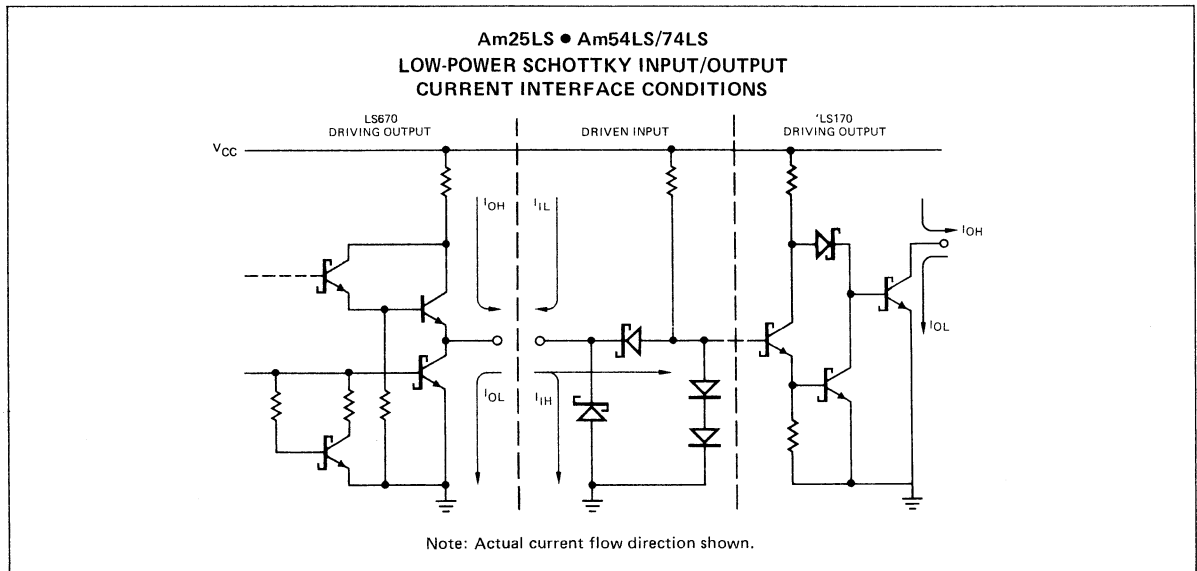
($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	Read Select R _A , R _B to Q _i							C _L = 15pF R _L = 2.0kΩ	
t _{PHL}									
t _{PLH}	Write Enable G _W to Q _i						ns		
t _{PHL}									
t _{PLH}	Data D _i to Q _i						ns		
t _{PHL}									
t _{PLH}	Read Enable G _R to Q _i						ns		
t _{PHL}									
t _s	D _i to G _W						ns		
t _s	W _A , W _B to G _W						ns		
t _H	D _i to G _W						ns		
t _H	W _A , W _B to G _W						ns		
t _{pw}	G _W or G _R						ns		
T _{LATCH}	Latch Time for New Data						ns		

**Am25LS170 ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE***

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
		T _A = 0°C to +70°C V _{CC} = 5.0V ±5%		T _A = -55°C to +125°C V _{CC} = 5.0V ±10%			
t _{PLH}	R _A , R _B , to Q _i					ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}							
t _{PLH}	G _W to Q _i					ns	
t _{PHL}							
t _{PLH}	D _i to Q _i					ns	
t _{PHL}							
t _{PLH}	G _R to Q _i					ns	
t _{PHL}							
t _s	D _i to G _W					ns	
t _s	W _A , W _B to G _W					ns	
t _H	D _i to G _W					ns	
t _H	W _A , W _B to G _W					ns	
t _{pw}	G _W or G _R					ns	
T _{LATCH}	Latch Time for New Data					ns	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.



Am25LS/54LS/74LS170/670

Am25LS670 • Am54LS/74LS670
SWITCHING CHARACTERISTICS

(T_A = 25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	Read Select R _A , R _B to Q _i							ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}									
t _{PLH}	Write Enable G _W to Q _i							ns	
t _{PHL}									
t _{PLH}	Data D _i to Q _i							ns	
t _{PHL}									
t _{ZH}	Read Enable G _R to Q _i							ns	
t _{ZL}									
t _{HZ}									
t _{LZ}									
t _s	D _i to G _W							ns	C _L = 5.0pF R _L = 2.0kΩ
t _s	W _A , W _B to G _W							ns	
t _H	D _i to G _W							ns	
t _H	W _A , W _B to G _W							ns	
t _{pw}	G _W or G _R							ns	
T _{LATCH}	Latch Time for New Data							ns	

Am25LS670 ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

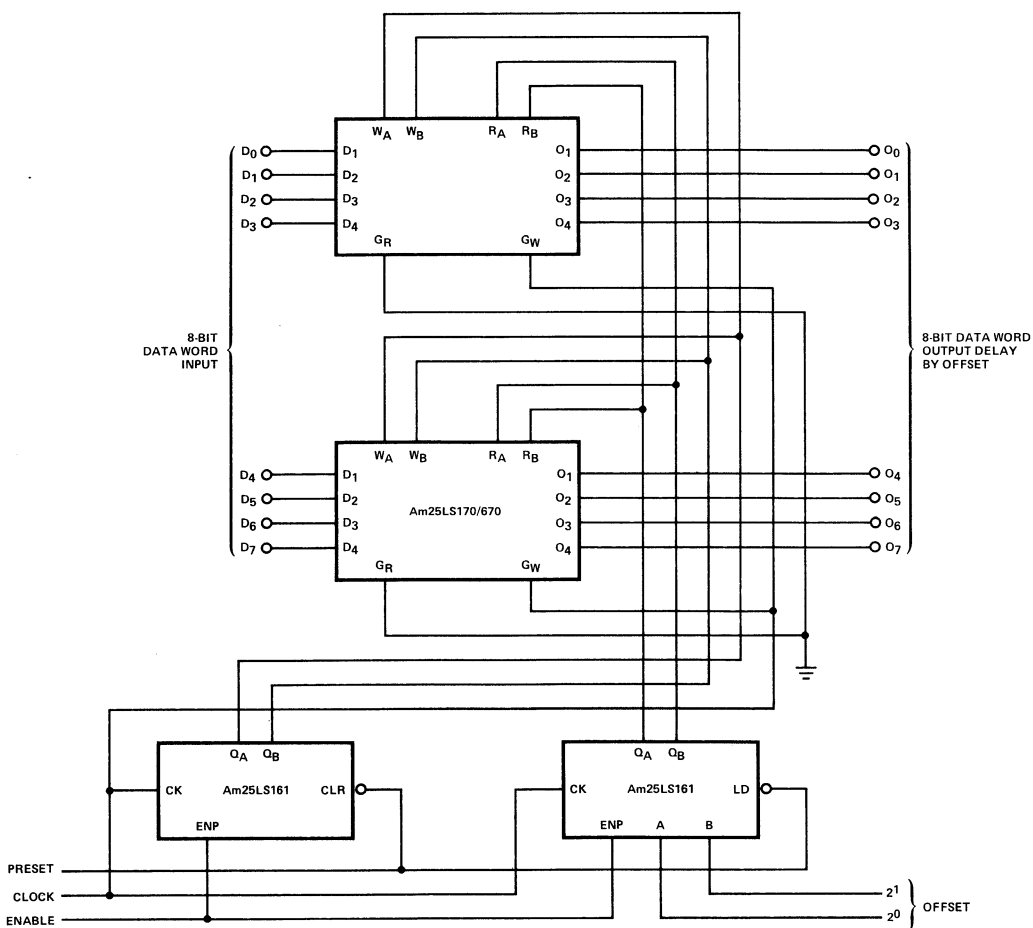
Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
		T _A = 0°C to +70°C V _{CC} = 5.0V ±5%		T _A = -55°C to +125°C V _{CC} = 5.0V ±10%			
t _{PLH}	Read Select R _A , R _B to Q _i					ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}							
t _{PLH}	Write Enable G _W to Q _i					ns	
t _{PHL}							
t _{PLH}	Data D _i to Q _i					ns	
t _{PHL}							
t _{ZH}	Read Enable G _R to Q _i					ns	
t _{ZL}							
t _{HZ}							
t _{LZ}							
t _s	D _i to G _W					ns	C _L = 5.0pF R _L = 2.0kΩ
t _s	W _A , W _B to G _W					ns	
t _H	D _i to G _W					ns	
t _H	W _A , W _B to G _W					ns	
t _{pw}	G _W or G _R					ns	
T _{LATCH}	Latch Time for New Data					ns	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

ORDERING INFORMATION

Package Type	Temperature Range	Am25LS170 Order Number	Am25LS670 Order Number	Am54LS/74LS170 Order Number	Am54LS/74LS670 Order Number
Molded DIP	0°C to +70°C	AM25LS170PC	AM25LS670PC	SN74LS170N	SN74LS670N
Hermetic DIP	0°C to +70°C	AM25LS170DC	AM25LS670DC	SN74LS170J	SN74LS670J
Dice	0°C to +70°C	AM25LS170XC	AM25LS670XC	SN74LS170X	SN74LS670X
Hermetic DIP	-55°C to +125°C	AM25LS170DM	AM25LS670DM	SN54LS170J	SN54LS670J
Hermetic Flat Pak	-55°C to +125°C	AM25LS170FM	AM25LS670FM	SN54LS170W	SN54LS670W
Dice	-55°C to +125°C	AM25LS170XM	AM25LS670XM	SN54LS170X	SN54LS670X

APPLICATION



Delay variable by clock times offset 0, 1, 2, 3. System is expandable in width and length and is the basis of a digital auto correlator.

Variable Digital Delay Buffer (Auto Correlator)

Am25LS174 • Am54LS/74LS174

Am25LS175 • Am54LS/74LS175

Hex/Quadruple D-Type Flip Flops With Clear

DISTINCTIVE CHARACTERISTICS

- 4-bit and 6-bit parallel registers
- Common clock and common clear
- Positive edge-triggered D flip-flops
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL}
 - Twice the fan-out over military range
 - 440 μ A source current
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am25LS174 is a six-bit register and the Am25LS175 is a four-bit register built using advanced Low Power Schottky technology. The registers consist of D-type flip-flops with a buffered common clock and an asynchronous active LOW buffered clear.

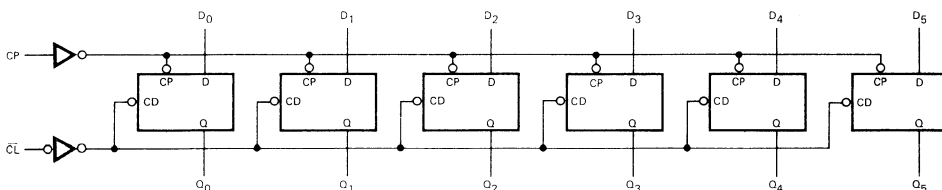
When the clear is LOW, the Q outputs are LOW independent of the other inputs. Information meeting the set-up requirements of the D inputs is transferred to the Q outputs on the positive-going edge of the clock pulse.

For versions of these devices having a common enable rather than clear see Am25LS07 and Am25LS08.

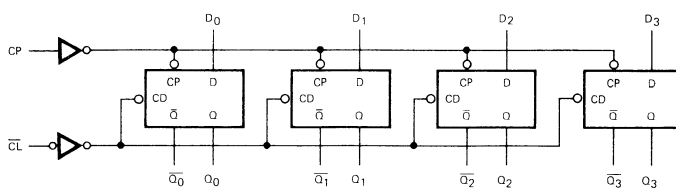
The Am54LS/74LS174 and 175 are standard performance versions of the Am25LS174 and 175. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAMS

'LS174



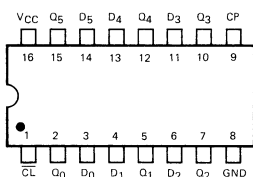
'LS175



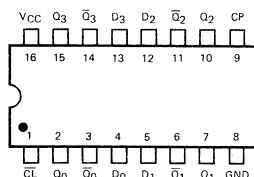
CONNECTION DIAGRAMS

Top Views

'LS174



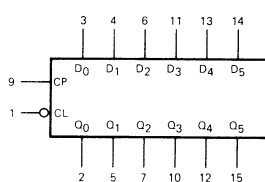
'LS175



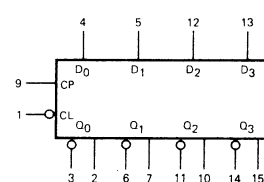
Note: Pin 1 is marked for orientation.

LOGIC SYMBOLS

'LS174



'LS175



V_{CC} = Pin 16
GND = Pin 8

ELECTRICAL CHARACTERISTICS The following conditions apply unless otherwise specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4\text{mA}$		0.4		Volts
			$I_{OL} = 8\text{mA}$		0.45		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7		Volts
			COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	Clock, \overline{CL}		-0.36		mA
			Others		-0.24		
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$	LS174		16	26	mA
			LS175		11	18	

Am54LS/74LS174/175**ELECTRICAL CHARACTERISTICS** The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	Am74LS	2.7	3.4		Volts
			Am54LS	2.5	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	All, $I_{OL} = 4\text{mA}$		0.4		Volts
			74LS only, $I_{OL} = 8\text{mA}$		0.5		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	Am54LS		0.7		Volts
			Am74LS		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.40	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-100	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$	LS174		16	26	mA
			LS175		11	18	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. All outputs open and 4.5V applied to the data and clear inputs. Measured after a momentary ground, then 4.5V applied to the clock input.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Clock to Output		15	23		20	30	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			13	20		23	35		
t_{PLH}	Clear to Q Output, LS175 only		16	25		16	25	ns	
t_{PHL}		Clear to Output		23	35		23		
t_{pw}	Pulse Width		Clock	17		20			
		Clear	20		20				
t_s	Data Set-up Time	20			20			ns	
t_s	Set-up Time Clear Recovery (in-active) to Clock	20			25			ns	
t_h	Data Hold Time	5			5			ns	
f_{max}	Maximum Clock Frequency (Note 1)	40	65		30	40		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

**Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE***

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$			
		$V_{CC} = 5.0\text{V} \pm 5\%$		$V_{CC} = 5.0\text{V} \pm 10\%$			
t_{PLH}	Clock to Output		34		39	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			30		35		
t_{PLH}	Clear to Q Output, LS175 only		37		42	ns	
t_{PHL}		Clear to Output		50			
t_{pw}	Pulse Width		Clock	26	30	35	
		Clear	30	35	35		
t_s	Data Set-up Time	30		35		ns	
t_s	Set-up Time Clear Recovery (In-active) to Clock	30		35		ns	
t_h	Data Hold Time	11		12		ns	
f_{max}	Maximum Clock Frequency (Note 1)	30		26		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

D_i The D flip-flop data inputs.

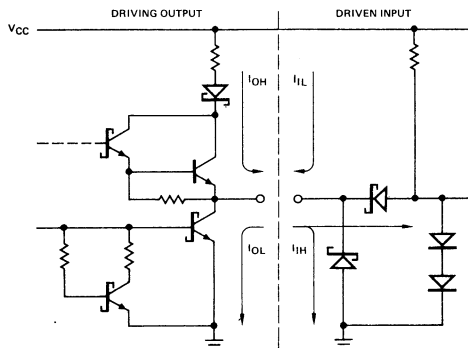
\overline{CL} Clear. When the clear is LOW, the Q_i outputs are LOW, regardless of the other inputs. When the clear is HIGH, data can be entered in the register.

CP Clock pulse for the register. Enters data on the positive transition.

Q_i The TRUE register outputs.

\overline{Q}_i The complement register outputs.

**Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**

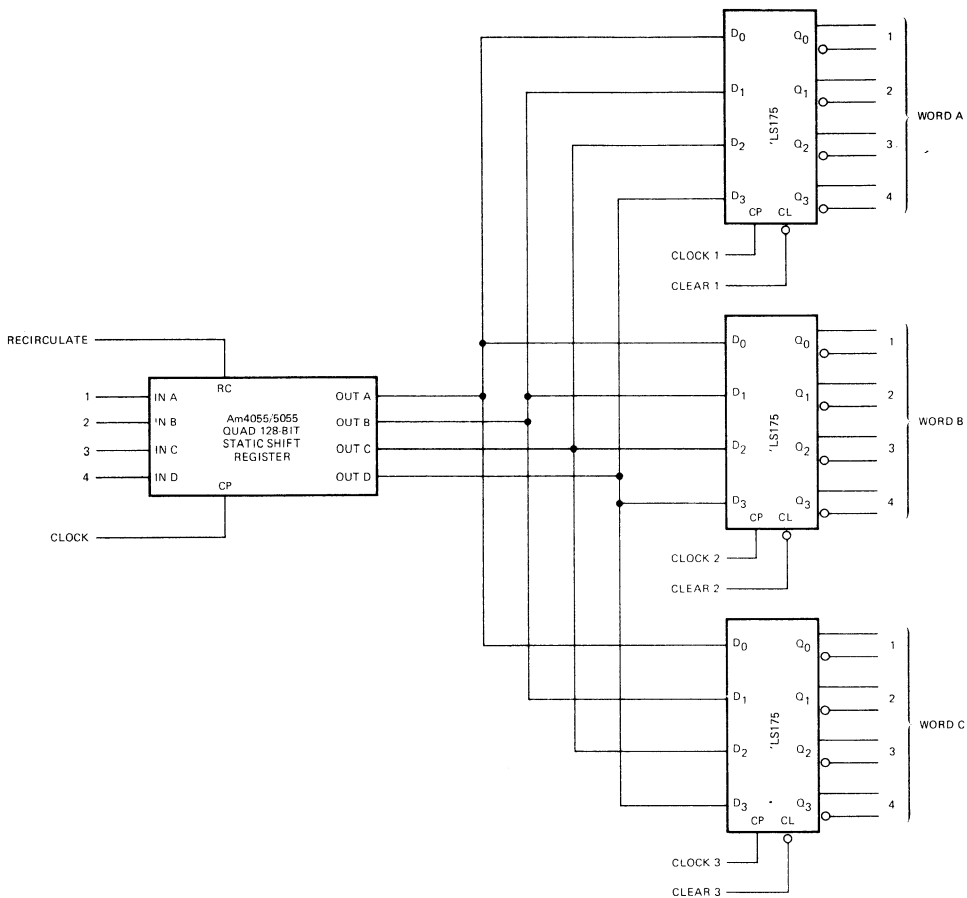


FUNCTION TABLE

INPUTS			OUTPUTS	
Clear	Clock	D_i	Q_i	\overline{Q}_i
L	X	X	L	H
H	L	X	NC	NC
H	H	X	NC	NC
H	↑	L	L	H
H	↑	H	H	L

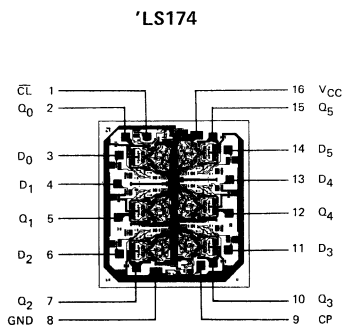
H = HIGH
 L = LOW
 ↑ = LOW-to-HIGH Transition
 X = Don't Care
 NC = No Change
 Note: \overline{Q}_i on Am25LS175 only.
 Q_i on Am54LS/74LS175 only.

APPLICATION

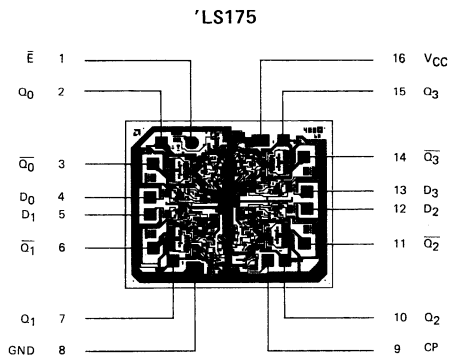


Low-Power Schottky registers interface directly with many MOS shift registers.

Metallization and Pad Layouts



DIE SIZE 0.075" X 0.084"



DIE SIZE 0.075" X 0.061"

Am25LS181 • Am54LS/74LS181

Four-Bit Arithmetic Logic Unit/Function Generator

DISTINCTIVE CHARACTERISTICS

- Performs 16 arithmetic operations including add, subtract, double and compare
- Full look-ahead capability for high speed arithmetic operation on long words
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL}
 - Twice the fan-out over military range
 - 440 μ A source current
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am25LS181 is a 4-bit, high-speed parallel Arithmetic Logic Unit (ALU)/Digital Function Generator. When the mode control (M) is LOW the 16 arithmetic operations are performed under the control of the four select inputs. When the mode control is HIGH the sixteen logic operations are performed on an individual bit basis between the two 4-bit parallel words under the control of the four select inputs.

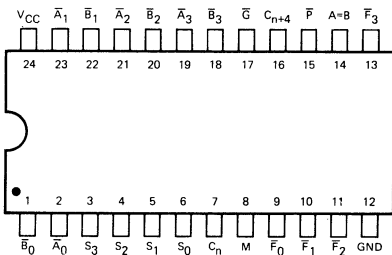
An internal full look-ahead carry scheme is used for high-speed arithmetic operations and provision is made for further look-ahead by including both carry propagate (P) and carry generate (G) outputs.

An open collector output A = B is used to signal the equivalence of the two parallel words. The open collector feature allows for the equivalence function to be expanded as a wired-AND connection for larger word lengths.

In many systems, the carry output C_{n+4} is connected to the next higher C_n to provide ripple block arithmetic. The ALU can be used with either active HIGH or active LOW inputs and can be ripple expanded or full look-ahead expanded in either mode. The connection pattern is identical for either logic representation.

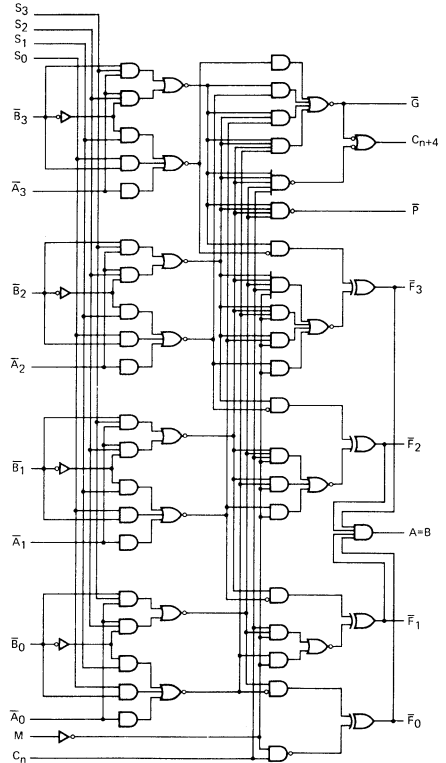
The Am54LS/74LS181 is a standard performance version of the Am25LS181. See appropriate electrical characteristic tables for detailed Am25LS improvements.

CONNECTION DIAGRAM Top View

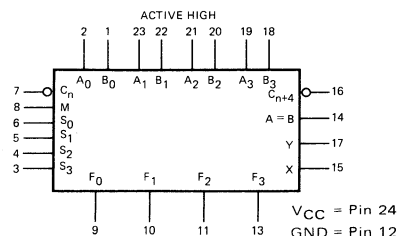
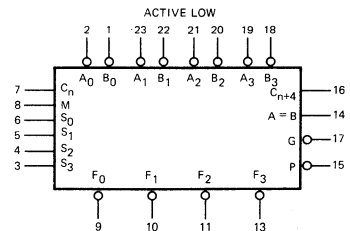


Note: Pin 1 is marked for orientation.

LOGIC DIAGRAM



LOGIC SYMBOLS



V_{CC} = Pin 24
GND = Pin 12

Am25LS181

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)MIL $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)		Units		
			Min.	Max.			
V_{OH}	Output HIGH Voltage (Except A = B Output)	$V_{CC} = \text{MIN.}$, $I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH}$ or V_{IL}	MIL	2.5	3.4	Volts	
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4\text{mA}$		0.4	Volts	
			$I_{OL} = 8\text{mA}$		0.45		
			$I_{OL} = 16\text{mA}$		0.55		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0		Volts		
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{OH}	Output HIGH Current for A = B Output	$V_{CC} = \text{MIN.}$, $V_{OH} = 5.5\text{V}$ $V_{IN} = V_{IH}$ or V_{IL}			100	μA	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$	M		-0.36	mA	
			\bar{A}_i or \bar{B}_i		-1.08		
			S_i		-1.44		
			C_n		-2.0		
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$	M		20	μA	
			\bar{A}_i or \bar{B}_i		60		
			S_i		80		
			C_n		100		
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 5.5\text{V}$	M		0.1	mA	
			\bar{A}_i or \bar{B}_i		0.3		
			S_i		0.4		
			C_n		0.5		
I_{SC}	Output Short Circuit Current (Note 3) (Except A = B Output)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$	A	MIL	20	32	mA
				COM'L	20	34	
			B	MIL	21	35	
				COM'L	21	37	

NOTES: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. I_{CC} is measured under two conditions – typ. and max. apply to both.A. S_i , M, A_i at 4.5V; all other inputs grounded; outputs open.B. S_i , M at 4.5V; all other inputs grounded; outputs open.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 24 to Pin 12) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to $+V_{CC}$ max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am25LS/54LS/74LS181

Am54LS/74LS181

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)		Units		
			Min.	Max.			
V _{OH}	Output HIGH Voltage (Except A = B Output)	V _{CC} = MIN., I _{OH} = -400μA V _{IN} = V _{IH} or V _{IL}	MIL	2.5	3.4	Volts	
			COM'L	2.7	3.4		
V _{OL}	Output LOW Voltage	V _{CC} = MIN. V _{IN} = V _{IH} or V _{IL}	All outputs, I _{OL} = 4mA	0.25	0.4	Volts	
			Am74LS only All outputs, I _{OL} = 8mA	0.35	0.5		
			\overline{G} , I _{OL} = 16 mA	0.47	0.7		
			\overline{P} , I _{OL} = 8mA	0.35	0.6		
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0		Volts		
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.5	Volts	
I _{OH}	Output HIGH Current for A = B Output	V _{CC} = MIN., V _{OH} = 5.5V V _{IN} = V _{IH} or V _{IL}			100	μA	
I _{IL}	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.4V	M		-0.36	mA	
			\overline{A}_i or \overline{B}_i		-1.08		
			S _i		-1.44		
			C _n		-2.0		
I _{IH}	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V	M		20	μA	
			\overline{A}_i or \overline{B}_i		60		
			S _i		80		
			C _n		100		
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V	M		0.1	mA	
			\overline{A}_i or \overline{B}_i		0.3		
			S _i		0.4		
			C _n		0.5		
I _{SC}	Output Short Circuit Current (Note 3) (Except A = B Output)	V _{CC} = MAX.	-15		-100	mA	
I _{CC}	Power Supply Current (Note 4)	V _{CC} = MAX.	A	MIL	20	32	mA
				COM'L	20	34	
			B	MIL	21	35	
				COM'L	21	37	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CC} is measured under two conditions - typ. and max. apply to both.
 A. S_i, M, A_i at 4.5V; all other inputs grounded; outputs open.
 B. S_i, M at 4.5V; all other inputs grounded; outputs open.

Am25LS181 • Am54LS/74LS181
SWITCHING CHARACTERISTICS
(T_A = 25°C, V_{CC} = 5.0V)(C_L = 15pF, R_L = 2.0kΩ)

Parameter	From (Input)	To (Output)	Am25LS181			Am54LS/74LS181			Units	Test Conditions
			Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	C _n	C _{n+4}			25		18	27	ns	
t _{PHL}					14		13	20		
t _{PLH}	C _n	F _i			19		17	26	ns	M = 0V (SUM or DIFF mode)
t _{PHL}					18		13	20		
t _{PLH}	A _i or B _i	G			25		19	29	ns	M = 0V, S ₀ = S ₃ = 4.5V, S ₁ = S ₂ = 0V (SUM mode)
t _{PHL}					23		15	23		
t _{PLH}	A _i or B _i	G			25		21	32	ns	M = 0V, S ₀ = S ₃ = 0V, S ₁ = S ₂ = 4.5V (DIFF mode)
t _{PHL}					25		17	26		
t _{PLH}	A _i or B _i	P			26		20	30	ns	M = 0V, S ₀ = S ₃ = 4.5V, S ₁ = S ₂ = 0V (SUM mode)
t _{PHL}					26		20	30		
t _{PLH}	A _i or B _i	P			26		20	30	ns	M = 0V, S ₀ = S ₃ = 0V, S ₁ = S ₂ = 4.5V (DIFF mode)
t _{PHL}					26		22	33		
t _{PLH}	A _i or B _i	F _i (j ≥ i)			28		21	32	ns	M = 0V, S ₀ = S ₃ = 4.5V, S ₁ = S ₂ = 0V (SUM mode)
t _{PHL}					19		13	20		
t _{PLH}	A _i or B _i	F _i (j ≥ i)			30		21	32	ns	M = 0V, S ₀ = S ₃ = 0V, S ₁ = S ₂ = 4.5V (DIFF mode)
t _{PHL}					19		15	23		
t _{PLH}	A _i or B _i	F _i			31		22	33	ns	M = 4.5V (LOGIC mode)
t _{PHL}					25		19	29		
t _{PLH}	A _i or B _i	C _{n+4}			33		25	38	ns	M = 0V, S ₀ = S ₃ = 4.5V, S ₁ = S ₂ = 0V (SUM mode)
t _{PHL}					31		25	38		
t _{PLH}	A _i or B _i	C _{n+4}			35		27	41	ns	M = 0V, S ₀ = S ₃ = 0V, S ₁ = S ₂ = 4.5V (DIFF mode)
t _{PHL}					35		27	41		
t _{PLH}	A _i or B _i	A = B			50		33	50	ns	M = 0V, S ₀ = S ₃ = 0V, S ₁ = S ₂ = 4.5V (DIFF mode)
t _{PHL}					45		41	62		
t _{PLH}	A _i or B _i	F _{i+1}			36				ns	S ₁ = S ₂ = M = 0V S ₀ = S ₃ = 4.5V (SUM mode)
t _{PHL}					53					
t _{PLH}	A _i or B _i	F _{i+1}			36				ns	S ₀ = S ₃ = M = 0V S ₁ = S ₂ = 4.5V (DIFF mode)
t _{PHL}					53					

3

OPERATION TABLE

SELECTION					ACTIVE-HIGH DATA			ACTIVE-LOW DATA							
					M = H Logic Functions					M = L; Arithmetic Operations			M = L; Arithmetic Operations		
										C _n = H (No Carry)		C _n = L (With Carry)	C _n = L (No Carry)		C _n = H (With Carry)
S ₃	S ₂	S ₁	S ₀												
L	L	L	L		F = A	F = A	F = A Plus 1	F = A	F = A Minus 1	F = A					
L	L	L	H		F = A + B	F = A + B	F = (A + B) Plus 1	F = AB	F = AB Minus 1	F = AB					
L	L	H	L		F = A + B	F = A + B	F = (A + B) Plus 1	F = A + B	F = AB Minus 1	F = AB					
L	L	H	H		F = Minus 1 (2's Compl.)	F = Minus 1 (2's Compl.)	F = Zero	F = 1	F = Minus 1 (2's Compl.)	F = Zero					
L	H	L	L		F = A + AB	F = A Plus AB	F = A Plus AB Plus 1	F = A + B	F = A Plus (A + B)	F = A Plus (A + B) Plus 1					
L	H	L	H		F = (A + B) Plus AB	F = (A + B) Plus AB	F = (A + B) Plus AB Plus 1	F = B	F = AB Plus (A + B)	F = AB Plus (A + B) Plus 1					
L	H	H	L		F = A ⊖ B	F = A Minus B Minus 1	F = A Minus B	F = A + B	F = A Minus B Minus 1	F = A Minus B					
L	H	H	H		F = AB	F = AB Minus 1	F = AB	F = A + B	F = A + B	F = (A + B) Plus 1					
H	L	L	L		F = A + B	F = A Plus AB	F = A Plus AB Plus 1	F = AB	F = A Plus (A + B)	F = A Plus (A + B) Plus 1					
H	L	L	H		F = A + B	F = A Plus B	F = A Plus B Plus 1	F = A ⊖ B	F = A Plus B	F = A Plus B Plus 1					
H	L	H	L		F = B	F = (A + B) Plus AB	F = (A + B) Plus AB Plus 1	F = B	F = AB Plus (A + B)	F = AB Plus (A + B) Plus 1					
H	L	H	H		F = AB	F = AB Minus 1	F = AB	F = A + B	F = A + B	F = (A + B) Plus 1					
H	H	L	L		F = 1	F = A Plus A*	F = A Plus A Plus 1	F = 0	F = A Plus A*	F = A Plus A Plus 1					
H	H	L	H		F = (A + B) Plus A	F = (A + B) Plus A	F = (A + B) Plus A Plus 1	F = AB	F = AB Plus A	F = AB Plus A Plus 1					
H	H	H	L		F = (A + B) Plus A	F = (A + B) Plus A	F = (A + B) Plus A Plus 1	F = AB	F = AB Plus A	F = AB Plus A Plus 1					
H	H	H	H		F = A	F = A Minus 1	F = A	F = A	F = A	F = A Plus 1					

* Each bit is shifted to the next more significant position.

Am25LS ONLY
 SWITCHING CHARACTERISTICS
 OVER OPERATING RANGE*
 ($C_L = 50\text{pF}$, $R_L = 2.0\text{k}\Omega$)

			Am25LS COM'L		Am25LS MIL		Units	Test Conditions
			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$			
Parameters	From (Input)	To (Output)	Min.	Max.	Min.	Max.		
t_{PLH}	C_n	C_{n+4}		37		42	ns	
t_{PHL}				22		26		
t_{PLH}	C_n	\bar{F}_i		29		33	ns	M = 0V (SUM or DIFF mode)
t_{PHL}				28		32		
t_{PLH}	\bar{A}_i or \bar{B}_i	\bar{G}		37		42	ns	M = 0V, $S_0 = S_3 = 4.5\text{V}$, $S_1 = S_2 = 0\text{V}$ (SUM mode)
t_{PHL}				34		39		
t_{PLH}	\bar{A}_i or \bar{B}_i	\bar{G}		37		42	ns	M = 0V, $S_0 = S_3 = 0\text{V}$, $S_1 = S_2 = 0\text{V}$ (DIFF mode)
t_{PHL}				37		42		
t_{PLH}	\bar{A}_i or \bar{B}_i	\bar{P}		38		44	ns	M = 0V, $S_0 = S_3 = 4.5\text{V}$, $S_1 = S_2 = 0\text{V}$ (SUM mode)
t_{PHL}				38		44		
t_{PLH}	\bar{A}_i or \bar{B}_i	\bar{P}		38		44	ns	M = 0V, $S_0 = S_3 = 4.5\text{V}$, $S_1 = S_2 = 4.5\text{V}$ (DIFF mode)
t_{PHL}				38		44		
t_{PLH}	\bar{A}_i or \bar{B}_i	\bar{F}_i ($j \geq i$)		41		47	ns	M = 0V, $S_0 = S_3 = 4.5\text{V}$, $S_1 = S_2 = 0\text{V}$ (SUM mode)
t_{PHL}				29		33		
t_{PLH}	\bar{A}_i or \bar{B}_i	\bar{F}_i ($j \geq i$)		43		50	ns	M = 0V, $S_0 = S_3 = 0\text{V}$, $S_1 = S_2 = 4.5\text{V}$ (DIFF mode)
t_{PHL}				29		33		
t_{PLH}	\bar{A}_i or \bar{B}_i	\bar{F}_i		44		51	ns	M = 4.5V (LOGIC mode)
t_{PHL}				37		42		
t_{PLH}	\bar{A}_i or \bar{B}_i	C_{n+4}		47		54	ns	M = 0V, $S_0 = S_3 = 4.5\text{V}$, $S_1 = S_2 = 0\text{V}$ (SUM mode)
t_{PHL}				44		51		
t_{PLH}	\bar{A}_i or \bar{B}_i	C_{n+4}		50		57	ns	M = 0V, $S_0 = S_3 = 0\text{V}$, $S_1 = S_2 = 4.5\text{V}$ (DIFF mode)
t_{PHL}				50		57		
t_{PLH}	\bar{A}_i or \bar{B}_i	A = B		69		80	ns	M = 0V, $S_0 = S_3 = 0\text{V}$, $S_1 = S_2 = 4.5\text{V}$ (DIFF mode)
t_{PHL}				62		72		
t_{PLH}	\bar{A}_i or \bar{B}_i	\bar{F}_{i+1}		51		59	ns	$S_1 = S_2 = M = 0\text{V}$, $S_0 = S_3 = 4.5\text{V}$ (SUM mode)
t_{PHL}				69		80		
t_{PLH}	\bar{A}_i or \bar{B}_i	\bar{F}_{i+1}		51		59	ns	$S_0 = S_3 = M = 0\text{V}$, $S_1 = S_2 = 4.5\text{V}$ (DIFF mode)
t_{PHL}				69		80		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

$\bar{A}_0, \bar{A}_1, \bar{A}_2, \bar{A}_3$ The A data inputs.

$\bar{B}_0, \bar{B}_1, \bar{B}_2, \bar{B}_3$ The B data inputs.

S_0, S_1, S_2, S_3 The control inputs used to determine the arithmetic or logic function performed.

$\bar{F}_0, \bar{F}_1, \bar{F}_2, \bar{F}_3$ The data outputs of the ALU.

M The mode control inputs used to select either the arithmetic or logic operations.

C_n The carry-in input of the ALU.

C_{n+4} The carry-look-ahead output of the four-bit input field.

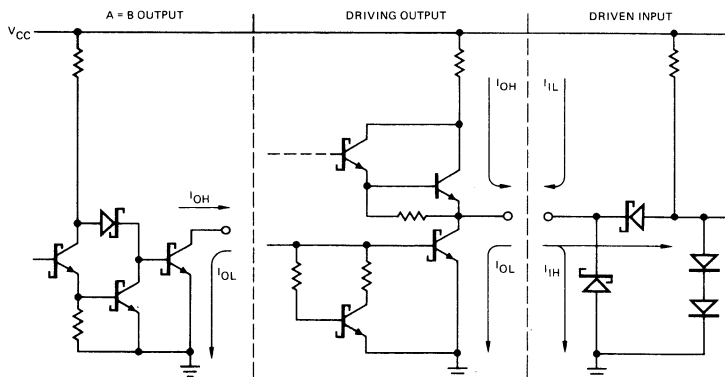
\bar{G} The carry-generate output for use in multi-level look-ahead schemes.

\bar{P} The carry-propagate output for use in multi-level look-ahead schemes.

A = B The open collector comparator output that can be used to determine equivalence. This output is HIGH whenever the four F outputs are HIGH.

USER NOTES

1. Throughout this data sheet, the active LOW input and output terminology has been used. For the active HIGH definition, the nomenclature shown under the active HIGH logic symbol should be substituted.
2. Arithmetic operations are performed on a word basis.
3. Logic operations are performed on a bit basis.
4. Arithmetic in 1's complement notation requires an end around carry.
5. Subtraction in 2's complement notation requires a carry in ($C_n = \text{HIGH}$) for the active LOW case and ($\bar{C}_n = \text{LOW}$) for the active HIGH case.
6. The **A = B** output only indicates that the four \bar{F} outputs are all HIGH.

LOW POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS

Note: Actual current flow direction shown.

DIFF MODE TEST TABLE

FUNCTION INPUTS: $S_1 = S_2 = 4.5V$, $S_0 = S_3 = M = 0V$

Parameter	Under Test	Other Input Same Bit		Other Data Inputs		Output Under Test	Output Waveform
		Apply 4.5V	Apply 0V	Apply 4.5V	Apply 0V		
t_{PLH} t_{PHL}	\bar{A}_i	None	\bar{B}_i	Remaining \bar{A}	Remaining \bar{B} , C_n	\bar{F}_i	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	Remaining \bar{A}	Remaining \bar{B} , C_n	\bar{F}_i	Out-of-Phase
t_{PLH} t_{PHL}	\bar{A}_i	None	\bar{B}_i	None	Remaining \bar{A} and \bar{B} , C_n	\bar{P}	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	None	Remaining \bar{A} and \bar{B} , C_n	\bar{P}	Out-of-Phase
t_{PLH} t_{PHL}	\bar{A}_i	\bar{B}_i	None	None	Remaining \bar{A} and \bar{B} , C_n	\bar{G}	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	None	\bar{A}_i	None	Remaining \bar{A} and \bar{B} , C_n	\bar{G}	Out-of-Phase
t_{PLH} t_{PHL}	\bar{A}_i	None	\bar{B}_i	Remaining \bar{A}	Remaining \bar{B} , C_n	$A = B$	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	Remaining \bar{A}	Remaining \bar{B} , C_n	$A = B$	Out-of-Phase
t_{PLH} t_{PHL}	\bar{A}_i	\bar{B}_i	None	None	Remaining \bar{A} and \bar{B} , C_n	C_{n+4}	Out-of-Phase
t_{PLH} t_{PHL}	\bar{B}_i	None	\bar{A}_i	None	Remaining \bar{A} and \bar{B} , C_n	C_{n+4}	In-Phase
t_{PLH} t_{PHL}	C_n	None	None	All \bar{A} and \bar{B}	None	Any \bar{F} or C_{n+4}	In-Phase

SUM MODE TEST TABLE

FUNCTION INPUTS: $S_0 = S_3 = 4.5V$, $S_1 = S_2 = M = 0V$

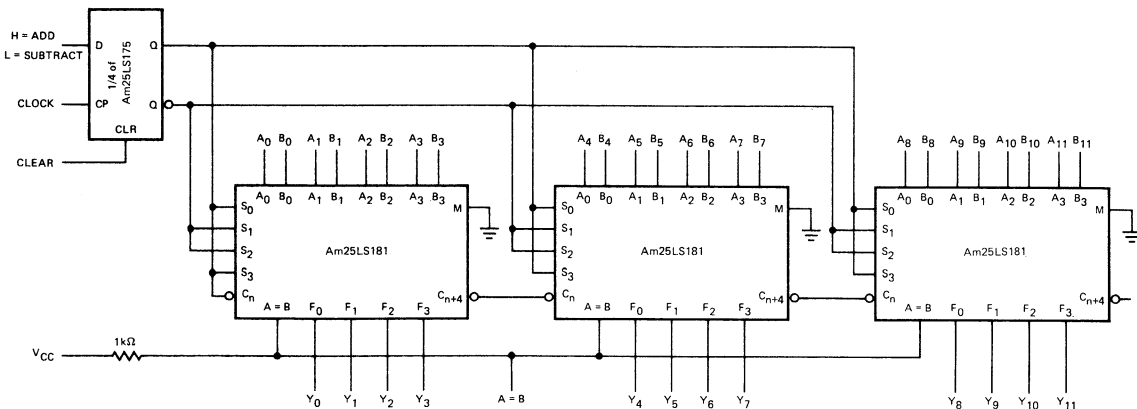
Parameter	Input Under Test	Other Input Same Bit		Other Data Inputs		Output Under Test	Output Waveform
		Apply 4.5V	Apply 0V	Apply 4.5V	Apply 0V		
t_{PLH} t_{PHL}	\bar{A}_i	\bar{B}_i	None	Remaining \bar{A} and \bar{B}	C_n	\bar{F}_i	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	Remaining \bar{A} and \bar{B}	C_n	\bar{F}_i	In-Phase
t_{PLH} t_{PHL}	\bar{A}_i	\bar{B}_i	None	None	Remaining \bar{A} and \bar{B} , C_n	\bar{P}	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	None	Remaining \bar{A} and \bar{B} , C_n	\bar{P}	In-Phase
t_{PLH} t_{PHL}	\bar{A}_i	None	\bar{B}_i	Remaining \bar{B}	Remaining \bar{A} , C_n	\bar{G}	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	None	\bar{A}_i	Remaining \bar{B}	Remaining \bar{A} , C_n	\bar{G}	In-Phase
t_{PLH} t_{PHL}	\bar{A}_i	None	\bar{B}_i	Remaining \bar{B}	Remaining \bar{A} , C_n	C_{n+4}	Out-of-Phase
t_{PLH} t_{PHL}	\bar{B}_i	None	\bar{A}_i	Remaining \bar{B}	Remaining \bar{A} , C_n	C_{n+4}	Out-of-Phase
t_{PLH} t_{PHL}	C_n	None	None	All \bar{A}	All \bar{B}	Any \bar{F} or C_{n+4}	In-Phase

LOGIC MODE TEST TABLE

FUNCTION INPUTS: $S_1 = S_2 = M = 4.5V$, $S_0 = S_3 = 0V$

Parameter	Input Under Test	Other Input Same Bit		Other Data Inputs		Output Under Test	Output Waveform
		Apply 4.5V	Apply 0V	Apply 4.5V	Apply 0V		
t_{PLH} t_{PHL}	\bar{A}_i	\bar{B}_i	None	None	Remaining \bar{A} and \bar{B} , C_n	\bar{F}_i	Out-of-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	None	Remaining \bar{A} and \bar{B} , C_n	\bar{F}_i	Out-of-Phase

APPLICATIONS



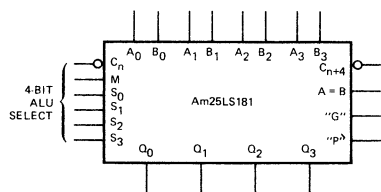
12-BIT ADDER/SUBTRACTOR (2'S COMPLEMENT)

FUNCTION TABLE

A = Active HIGH B = Active LOW

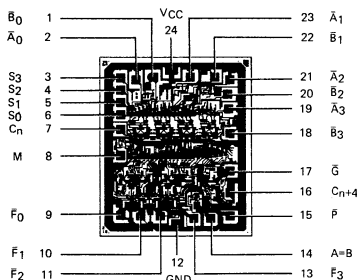
S ₀	S ₁	S ₂	S ₃	Arithmetic (M = L, C _n = H)	Logic (M = H)
L	L	L	L	A	\bar{A}
H	L	L	L	$A + \bar{B}$	$\bar{A}B$
L	H	L	L	A + B	$\bar{A}\bar{B}$
H	H	L	L	minus 1 (2's comp.)	Logic '0'
L	L	H	L	A plus AB	AB
H	L	H	L	AB plus [A + \bar{B}]	B
L	H	H	L	A plus B	$\bar{A} \oplus \bar{B}$
H	H	H	L	AB minus 1	AB
L	L	L	H	A plus $\bar{A}\bar{B}$	$\bar{A} + \bar{B}$
H	L	L	H	A minus B minus 1	$A \oplus B$
L	H	L	H	$\bar{A}\bar{B}$ plus [A + B]	\bar{B}
H	H	L	H	$\bar{A}\bar{B}$ minus 1	$\bar{A}\bar{B}$
L	L	H	H	A plus A (2 x A)	Logic '1'
H	L	H	H	A plus [A + \bar{B}]	A + B
L	H	H	H	A plus [A + B]	$A + \bar{B}$
H	H	H	H	A minus 1	A

If one input is defined active-HIGH and the second input is defined active-LOW, the sixteen arithmetic and logic functions of the ALU are reordered as shown in the function table.



L = Low Voltage Level
H = High Voltage Level

Metallization and Pad Layout



DIE SIZE : 0.078" X 0.092"

3

Am25LS190 • Am54LS/74LS190

Am25LS191 • Am54LS/74LS191

Synchronous Counters With Up/Down Mode Control

DISTINCTIVE CHARACTERISTICS

- Single up/down countline
- Parallel load inputs and parallel count outputs
- Ripple clock output for cascading
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL}
 - Twice the fan-out over military range
 - 440 μ A source current
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am25LS190 and Am25LS191 are BCD and binary synchronous up/down counters. The counter flip-flops are triggered on the LOW-to-HIGH transition of the clock input if the enable input is LOW. If the enable input is HIGH, counting is inhibited.

The direction of the count sequence is controlled by the up/down input. When the up/down input is LOW, the counter will count up. When the up/down input is HIGH, the counter will count down.

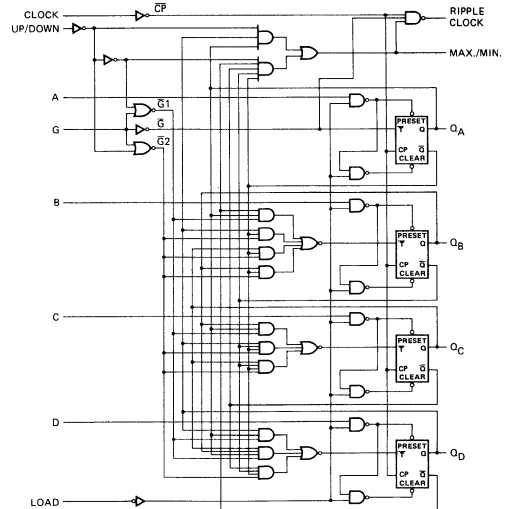
The load input is used to asynchronously jam new data into the counter via the parallel data inputs. When the load input is LOW, the counter flip-flop outputs will follow the parallel data inputs regardless of the clock input.

The max./min. count output is HIGH for a complete clock cycle when the counter overflows (binary 9 or binary 15) or underflows (binary 0). The ripple clock output is LOW for the LOW part of the clock cycle when the overflow or underflow condition exists. The counters are cascaded by connecting the ripple clock output to the enable input of the succeeding counter when parallel counting, or connecting the ripple clock output to the clock input when the parallel enable connection is used. The min./max. count output is used in high-speed look-ahead connection schemes.

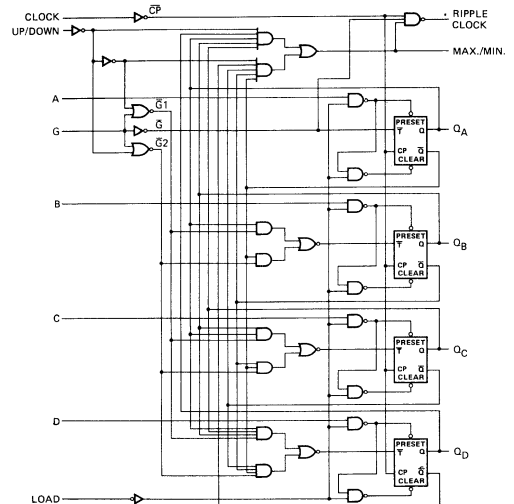
The Am54LS/74LS190 and 191 are standard performance versions of the Am25LS190 and 191. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAMS

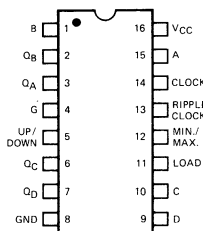
Am25LS190 Decade Counter



Am25LS191 Binary Counter

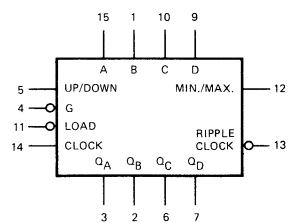


CONNECTION DIAGRAM – Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

ELECTRICAL CHARACTERISTICS Am25LS190 • Am25LS191

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)**DC CHARACTERISTICS OVER OPERATING RANGE**

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4\text{mA}$		0.2	0.4	Volts
			$I_{OL} = 8\text{mA}$			0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	Enable G			-1.08	mA
			Others			-0.36	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	Enable G			60	μA
			Others			20	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$	Enable G			0.3	mA
			Others			0.1	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)		20	35	mA	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. All inputs grounded and all outputs open.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into to Outputs	30mA
DC Input Current	-30mA to 5.0mA

Am25LS/54LS/74LS190/191

ELECTRICAL CHARACTERISTICS Am54LS/74LS190 • Am54LS/74LS191

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	All $I_{OL} = 4.0\text{mA}$		0.25	0.4	Volts
			Am74LS, $I_{OL} = 8.0\text{mA}$		0.35	0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	Enable G			-1.08	mA
			Others			-0.4	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	Enable G			60	μA
			Others			20	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$	Enable G			0.3	mA
			Others			0.1	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-100	mA
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)			20	35	mA

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. All inputs grounded and all outputs open.

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Load to Q		22	33		22	33	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			26	39		33	50		
t_{PLH}	A, B, C, D to Q_A, Q_B, Q_C, Q_D Respectively		14	22		20	32	ns	
t_{PHL}			24	39		27	40		
t_{PLH}	Clock to Ripple Clock		11	18		13	20	ns	
t_{PHL}			15	21		16	24		
t_{PLH}	Clock to Q		14	21		16	24	ns	
t_{PHL}			21	30		24	36		
t_{PLH}	Clock to Min./Max.		26	39		28	42	ns	
t_{PHL}			27	39		37	52		
t_{PLH}	Up/Down to Ripple Clock		30	45		30	45	ns	
t_{PHL}			30	45		30	45		
t_{PLH}	Up/Down to Min./Max.		21	33		21	33	ns	
t_{PHL}			22	33		22	33		
t_{PLH}	Enable to Ripple Clock		12	19		21	33	ns	
t_{PHL}			17	27		21	33		
f_{max}	Max. Clock Frequency (Note 1)	25	30		20	25		MHz	
t_{pw}	Clock Pulse Width	25			25			ns	
t_{pw}	Load Pulse Width	25			35			ns	
t_s	Data Set-up Time	12			20			ns	
t_s	Count Enable	30			40			ns	
t_h	Data Hold Time	0			0			ns	
t_r	MR - CP	20						ns	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		T _A = 0°C to +70°C V _{CC} = 5.0V ±5%		T _A = -55°C to +125°C V _{CC} = 5.0V ±10%			
		Min.	Max.	Min.	Max.		
t _{PLH}	Load to Q		47		54	ns	R _L = 2.0kΩ C _L = 50pF
t _{PHL}			55		63		
t _{PLH}	A, B, C, D to Q _A , Q _B Q _C , Q _D Respectively		33		38	ns	
t _{PHL}			55		63		
t _{PLH}	Clock to Ripple Clock		28		32	ns	
t _{PHL}			31		36		
t _{PLH}	Clock to Q		31		36	ns	
t _{PHL}			43		50		
t _{PLH}	Clock to Min./Max.		55		63	ns	
t _{PHL}			55		63		
t _{PLH}	Up/Down to Ripple Clock		63		72	ns	
t _{PHL}			63		72		
t _{PLH}	Up/Down to Min./Max.		47		54	ns	
t _{PHL}			47		54		
t _{PLH}	Enable to Ripple Clock		29		33	ns	
t _{PHL}			39		45		
f _{max}	Maximum Clock Frequency (Note1)	19		16		ns	
t _{pw}	Clock Pulse Width	37		42		ns	
t _{pw}	Load Pulse Width	37		42		ns	
t _s	Data Set-up Time	20		23		ns	
t _s	Count Enable	39		45		ns	
t _h	Data Hold Time	4		5		ns	
t _r	MR – CP	30		35		ns	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

A, B, C, D The four parallel data inputs to the counter flip-flops.

Q_A, Q_B, Q_C, Q_D The four outputs of the counter.

Clock The clock input causes the counter to change state in the count mode. The counter flip-flops trigger on the LOW-to-HIGH transition of the clock.

Enable The enable input can be used to enable or inhibit counting. When the enable input is HIGH, counting is inhibited.

Up/Down The up/down input controls the direction of the

count sequence. When the up/down input is LOW, the counter will count up (positive logic definitions).

Load The load input is used to parallel enter new data via the A, B, C and D inputs. When the load input is LOW, the counter will follow the parallel inputs regardless of the clock input.

Min./Max. The min./max. output is HIGH when the counter is in either the overflow or underflow state.

Ripple Clock The ripple clock output is LOW when the counter is in either the overflow or underflow state and the clock is LOW.

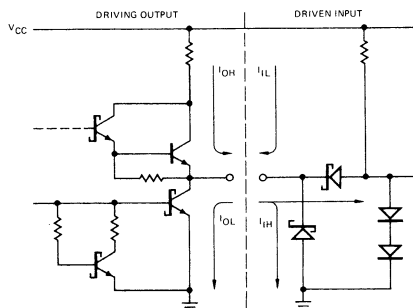
FUNCTION TABLE

INPUTS								OUTPUTS					COMMENTS	
Clock	Up/Dn	Enable G	A	B	C	D	Load	Q _A	Q _B	Q _C	Q _D	Min./Max.		Ripple Clock
X	X	H	X	X	X	X	H	NC	NC	NC	NC	NC	NC	Inhibit
X	X	X	L	L	L	L	L	L	L	L	L	H	CK	Underflow
X	X	X	H	H	H	H	L	H	H	H	H	H	CK	191 Overflow
X	X	X	H	L	L	H	L	H	L	L	H	H	CK	190 Overflow
X	X	X	L	H	L	H	L	L	H	L	H	L	H	Examples of no Overflow or Underflow
X	X	X	H	L	H	L	L	H	L	H	L	L	H	
↑	L	L	X	X	X	X	H	Count Up				A/R	A/R & CK	Count Up
↑	H	L	X	X	X	X	H	Count Down				A/R	A/R & CK	Count Down

H = HIGH
 L = LOW
 X = Don't Care
 ↑ = LOW-to-HIGH Transition

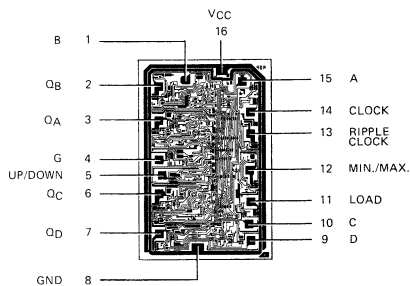
NC = No Change
 CK = LOW if Clock is LOW, HIGH if Clock is HIGH
 A/R = Assumes State Required by Counter Output

**Am25LS • Am54LS/74LS
 LOW-POWER SCHOTTKY INPUT/OUTPUT
 CURRENT INTERFACE CONDITIONS**



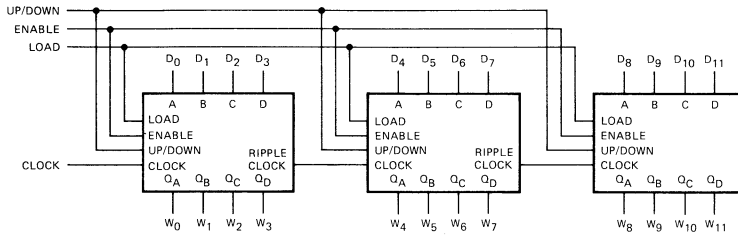
Note: Actual current flow direction shown.

Metallization and Pad Layout

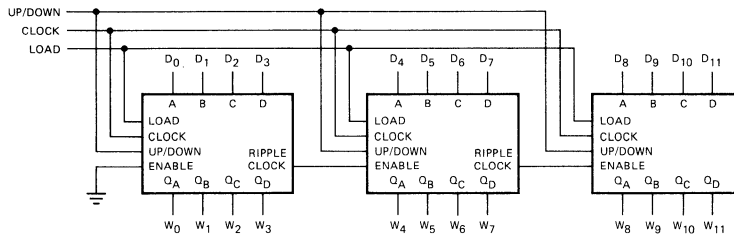


DIE SIZE 0.069" X 0.105"

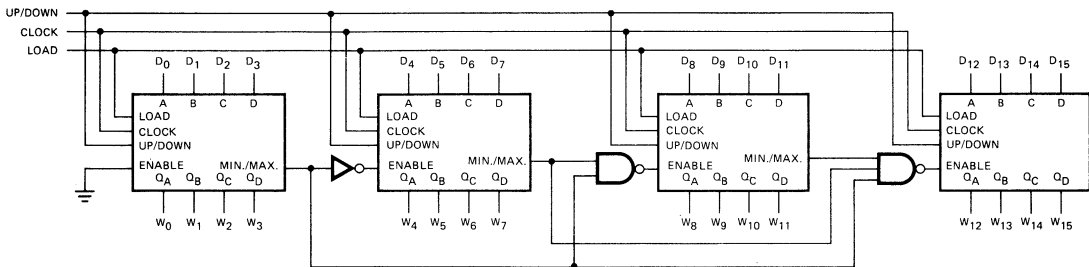
APPLICATIONS



PARALLEL ENABLE WITH RIPPLE CLOCK



SYNCHRONOUS PARALLEL COUNTING WITH RIPPLE ENABLE



SYNCHRONOUS COUNTING WITH FULL LOOK-AHEAD

Am25LS192 • Am25LS193 Am54LS/74LS192 • Am54LS/74LS193

Decimal and Hexadecimal Up/Down Counters

DISTINCTIVE CHARACTERISTICS

- Separate up and down clocks
- Asynchronous parallel load
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL} at $I_{OL} = 8mA$
 - Twice the fan-out over military range
 - 440 μA source current at HIGH output
- 100% product assurance screening to MIL-STD-883 requirements

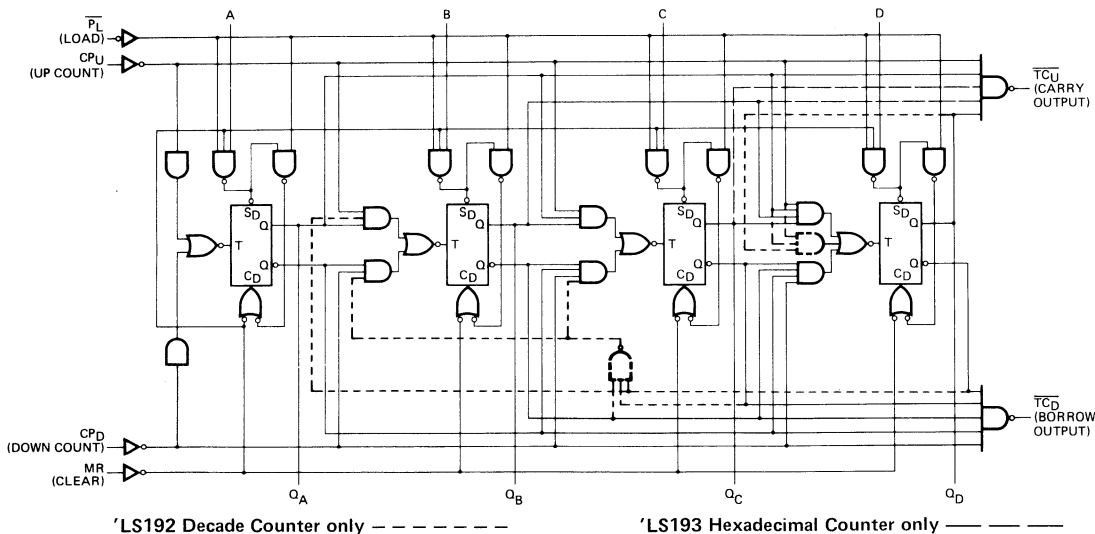
FUNCTIONAL DESCRIPTION

The 'LS192 and 'LS193 are four-bit up/down counters using advanced Low-Power Schottky processing. The 'LS192 counts in the BCD mode and the 'LS193 counts in the binary mode. These counters have separate count-up and count-down clock inputs (CP_U and CP_D , respectively). The Q_i outputs change state synchronously on the LOW-to-HIGH transition on either the up clock input or the down clock input. Only one clock input can be LOW at a time or erroneous counting will result.

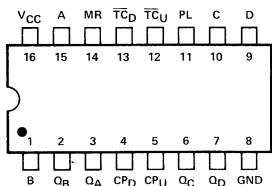
Each of the four flip-flops can be preset to a logic HIGH or a logic LOW by means of four parallel inputs (A, B, C, and D). When the parallel load input (\overline{PL}) goes LOW, all four flip-flops set to the state of the direct inputs (A, B, C, and D) independent of the clock inputs. An active HIGH master reset (MR) is provided which overrides both the clock and parallel load inputs forcing all Q_i outputs LOW.

Two terminal count outputs are gated with the clock inputs to provide clock signal to other counters. The TC_D output goes LOW when the counter is in state 0000 and the count down clock goes LOW. The TC_U goes LOW when the count up goes LOW and the counter is in state 1001 ('LS192) or state 1111 ('LS193). The TC_U and TC_D outputs can drive the count up and count down clocks on the next counter in a series. The Q_i outputs of such a connection scheme are not synchronous on cascaded counters in this series.

LOGIC DIAGRAM

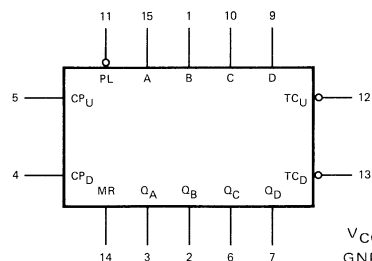


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

Am25LS192 • Am25LS193

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am25LS192XC/Am25LS193XC	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\% \text{ (COM'L)}$	MIN. = 4.75V	MAX. = 5.25V
Am25LS192XM/Am25LS193XM	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\% \text{ (MIL)}$	MIN. = 4.50V	MAX. = 5.50V

Parameters	Description	Test Conditions (Note 1)	Typ.		Units		
			Min.	(Note 2)		Max.	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4	Volts	
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.25	0.40	Volts
			$I_{OL} = 8.0\text{mA}$		0.35	0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.4	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)		19	34	mA	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. ICC is measured with all outputs open; clear and load inputs grounded; and all other inputs at 4.5V

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	$-65^\circ\text{C to } +150^\circ\text{C}$
Temperature (Ambient) Under Bias	$-55^\circ\text{C to } +125^\circ\text{C}$
Supply Voltage to Ground Potential Continuous	$-0.5\text{V to } +7.0\text{V}$
DC Voltage Applied to Outputs for High Output State	$-0.5\text{V to } +V_{CC} \text{ max.}$
DC Input Voltage	$-0.5\text{V to } +7.0\text{V}$
DC Output Current, Into Outputs	30mA
DC Input Current	$-30\text{mA to } +5.0\text{mA}$

Am25LS/54LS/74LS192/193

Am54LS/74LS192 • Am54LS/74LS193

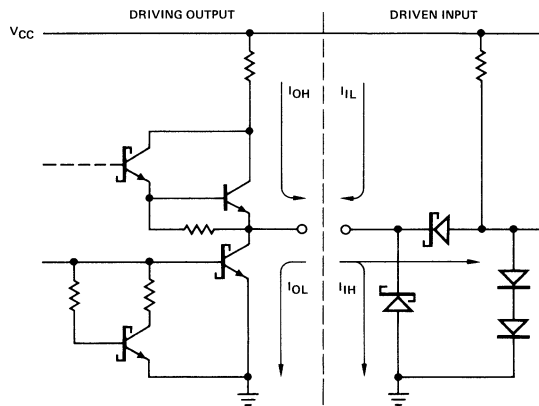
ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am74LS192X/74LS193X $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (COM'L) MIN. = 4.75V MAX. = 5.25V
 Am54LS192X/54LS193X $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIL) MIN. = 4.50V MAX. = 5.50V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)		Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}$ $V_{IN} = V_{IH}$ or V_{IL}	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH}$ or V_{IL}	All, $I_{OL} = 4.0\text{mA}$		0.25	0.40	Volts
			74LS only, $I_{OL} = 8.0\text{mA}$		0.35	0.50	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0				Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$				-0.4	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$				20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$				0.1	mA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15			-100	mA
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)		19		34	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CC} is measured with all outputs open; clear and load inputs grounded; and all other inputs at 4.5V

Am25LS • 54LS/74LS
 LOW-POWER SCHOTTKY INPUT/OUTPUT
 CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

SWITCHING CHARACTERISTICS

(T_A = 25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	CP _U or CP _D to Q _n		24	34		25	38	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			28	39		31	47		
t _{PLH}	CP _U to TC _U		10	15		17	26	ns	
t _{PHL}			10	15		21	33		
t _{PLH}	CP _D to TC _D		10	15		16	24	ns	
t _{PHL}			11	17		21	33		
t _{PLH}	A-D to Q _n Output		13	18			—	ns	
t _{PHL}			27	38			—		
t _{PLH}	A-D to TC _U Output		35	49			—	ns	
t _{PHL}			19	27			—		
t _{PLH}	A-D to TC _D Output		26	36			—	ns	
t _{PHL}			28	39			—		
t _{PHL}	MR Input to Q _n Output		20	29		22	35	ns	
t _{PLH}	MR Input to TC _U Output		25	35			—	ns	
t _{PHL}	MR Input to TC _D Output		16	22			—	ns	
t _{PLH}	P _L Input to Q _n Output		20	29		27	40	ns	
t _{PHL}			25	36		29	40		
t _{PLH}	P _L Input to TC _U Output		31	45			—	ns	
t _{PHL}			30	42			—		
t _{PLH}	P _L Input to TC _D Output		30	42			—	ns	
t _{PHL}			24	34			—		
t _s	Data Set-up Time A-D Input to P _L Input	Load 1	5.0			—		ns	
		Load 0	15			20		ns	
t _s	Set-up Time, P _L Input to CP _U or CP _D		9.0			—		ns	
t _s	Set-up Time, Clear Recovery (In-Active) to CP _U or CP _D		5.0			—		ns	
t _h	Data		0			0		ns	
t _{pw(0)}	Pulse Width	CP _U	11			20		ns	
		CP _D	11			20			
		P _L	9.0			20			
t _{pw(1)}	Pulse Width	MR	15			20		ns	
f _{max}	Maximum Clock Frequency, Count Up or Down (Note 1)		35	45		25	32	MHz	

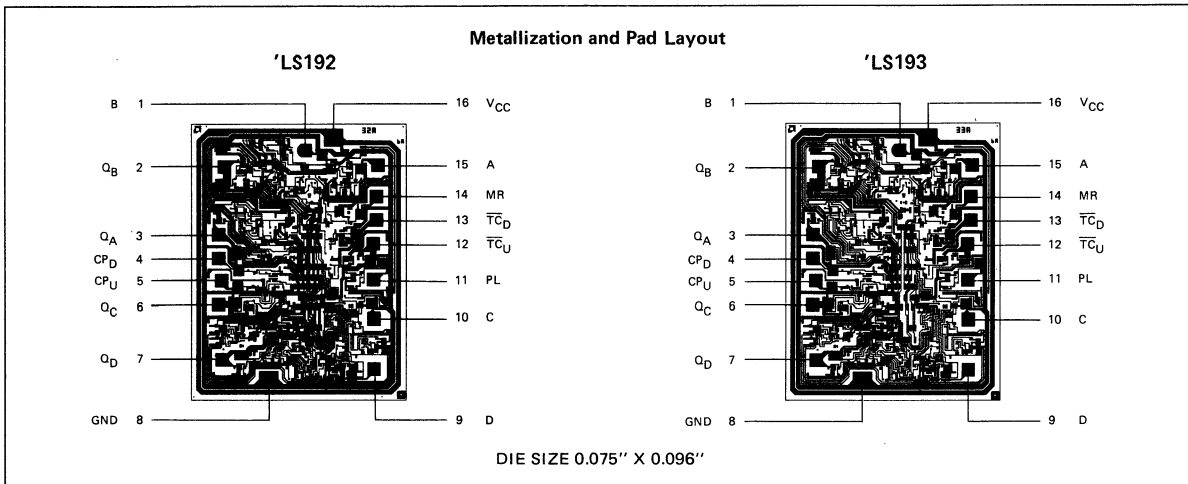
Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

Am25LS/54LS/74LS192/193

Am25LS192, Am25LS193 ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	CP _U or CP _D to Q _n		44		52	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			54		67		
t _{PLH}	CP _U to TC _U		22		26	ns	
t _{PHL}			23		27		
t _{PLH}	CP _D to TC _D		22		26	ns	
t _{PHL}			23		27		
t _{PLH}	A-D to Q _n Output		26		31	ns	
t _{PHL}			52		63		
t _{PLH}	A-D to TC _U Output		66		80	ns	
t _{PHL}			38		46		
t _{PLH}	A-D to TC _D Output		50		60	ns	
t _{PHL}			54		66		
t _{PHL}	MR Input to Q _n Output		41		50	ns	
t _{PLH}	MR Input to TC _U Output		49		60	ns	
t _{PHL}	MR Input to TC _D Output		32		38	ns	
t _{PLH}	P _L Input to Q _n Output		41		50	ns	
t _{PHL}			53		67		
t _{PLH}	P _L Input to TC _U Output		63		79	ns	
t _{PHL}			60		75		
t _{PLH}	P _L Input to TC _D Output		60		75	ns	
t _{PHL}			48		60		
t _s	Data Set-up Time A-D Input to P _L Input	Load 1	5.0		5.0	ns	
		Load 0	20		23		
t _s	Set-up Time, P _L Input to CP _U or CP _D		13		18	ns	
t _s	Set-up Time, Clear Recovery (In-Active) to CP _U or CP _D		7.0		9.0	ns	
t _h	Data		0		0	ns	
t _{pw(0)}	Pulse Width	CP _U	15		17	ns	
		CP _D	15		17		
		P _L	13		17		
t _{pw(1)}	Pulse Width	MR	18		21		
f _{max}	Maximum Clock Frequency, Count Up or Down (Note 1)		25		20	MHz	

* AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.



FUNCTION TABLE

INPUTS				OUTPUTS										Conditions	
Clock		Clear	Load	Data											
Up	Down			A	B	C	D	Q _A	Q _B	Q _C	Q _D	Borrow	Carry		
X	L	H	X	X	X	X	X	L	L	L	L	L	L	H	Clear
X	H	H	X	X	X	X	X	L	L	L	L	L	H	H	
X	X	L	L	D ₀	D ₁	D ₂	D ₃	D ₀	D ₁	D ₂	D ₃	X	X	Load	
H	↑	L	H	X	X	X	X	Count Down				H	H	Except at borrow	
H	L	L	H	X	X	X	X	L	L	L	L	L	L	H	Borrow
H	H	L	H	X	X	X	X	L	L	L	L	L	H	H	
↑	H	L	H	X	X	X	X	Count up				H	H	Except at carry	
L	H	L	H	X	X	X	X	H	H	H	H	H	L	Carry (193 only)	
H	H	L	H	X	X	X	X	H	H	H	H	H	H		
L	H	L	H	X	X	X	X	H	L	L	H	H	L	Carry (192 only)	
H	H	L	H	X	X	X	X	H	L	L	H	H	H		

H = HIGH X = Don't care
L = LOW ↑ = LOW-to-HIGH transition

D = A LOW or a HIGH and the respective output will assume the same state.

DEFINITION OF FUNCTIONAL TERMS

MR Clear. The clear input to the counter overrides all other inputs. When the clear input is HIGH, the Q outputs are set LOW independent of the other inputs.

PL Load. The load input performs asynchronous parallel load of the data on the A, B, C, and D inputs. When the load input is LOW, the Q_i outputs will follow the parallel inputs regardless of the clock inputs.

A, B, C, D The four parallel inputs to the counter flip-flops.

CP_U Count up. A clock input causing the counter to change state in an increasing binary number direction. Counting occurs on the LOW-to-HIGH transition of the clock.

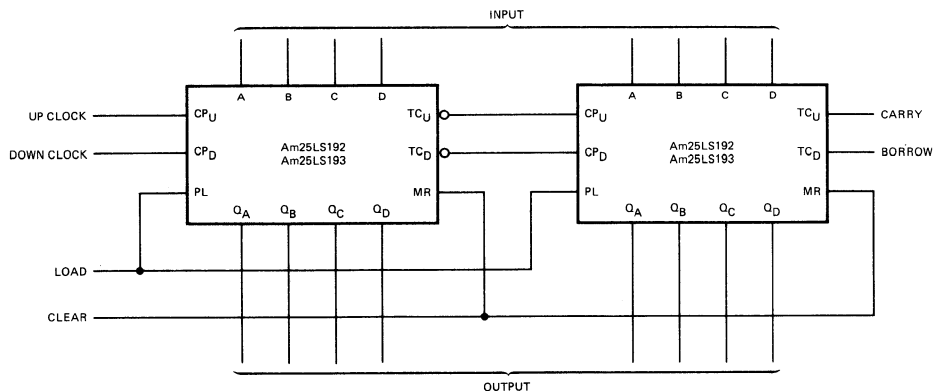
CP_D Count down. A clock input causing the counter to change state in a decreasing binary number direction. The state change occurs on the LOW-to-HIGH transition.

Q_A, Q_B, Q_C, Q_D The four outputs of the counter representing the LSB to MSB, respectively.

TC_U Carry output. A clock output that indicates the maximum upper binary number has been reached. For the 'LS192, TC_U indicates that the "9" state has been reached and the up clock is LOW. For the 'LS193, TC_U indicates that the "15" state has been reached and the up clock is LOW.

TC_D Borrow output. A clock output indicating that the "0" state has been reached and the down clock is LOW.

APPLICATION



8-Bit Up/Down Counter with Parallel Load

Am25LS194A • Am54LS/74LS194A

Am25LS195A • Am54LS/74LS195A

Four-Bit High-Speed Shift Registers

DISTINCTIVE CHARACTERISTICS

- Shift right or parallel load with JK inputs on Am25LS195A
- Shift left, right, parallel load or do nothing on Am25LS194A
- Fully synchronous shifting and parallel loading
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL}
 - Twice the fan-out over military range
 - 440 μ A source current
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am25LS194A and Am25LS195A are 4-bit registers that exhibit fully synchronous operation in all operating modes. The Am25LS195A can either parallel load all four register bits via the parallel inputs (A, B, C, D) or shift each of the four register bits right one place. The shifting or parallel loading is under control of the shift/load input (S/L). When the shift/load input is LOW, data is loaded from the parallel data inputs; when the shift/load input is HIGH, data is loaded from the register bits on the left. The first bit, Q_A , is loaded via the J and K inputs in the shift mode.

The Am25LS194A operates in four modes under control of the two select inputs, S_0 and S_1 . The four modes are parallel load (data comes from the parallel inputs), shift right (data comes from the flip-flop to the left, with the Q_A bit input from R), shift left (data comes from the flip-flop to the right, with the Q_D input from L), and hold or do nothing (each flip-flop receives data from its own output).

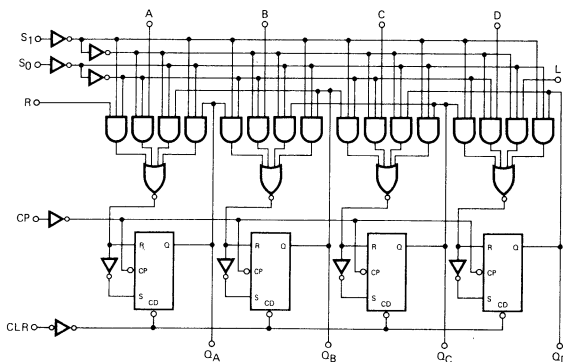
For both devices the outputs change state synchronously following a LOW-to-HIGH transition on the clock input, CP. Both devices have an active-LOW synchronous clear (CLR) which forces all outputs to the LOW state (\bar{Q}_D HIGH) independent of any other inputs.

Because all the flip-flops are D-type they do not catch 0's or 1's, and the only requirements on any inputs is that they meet the short set-up and hold time intervals with respect to the clock LOW-to-HIGH transition.

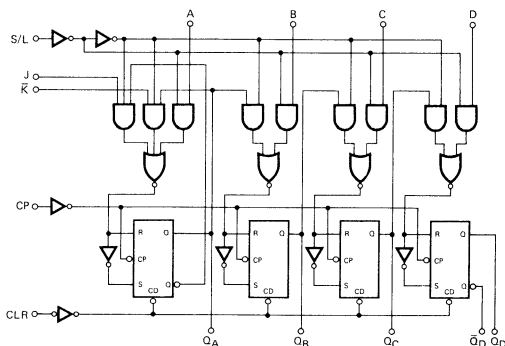
The Am54LS/74LS194A and 195A are standard performance versions of the Am25LS194A and 195A. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAMS

'LS194A



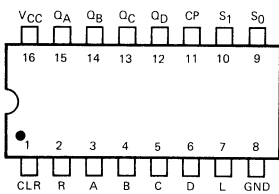
'LS195A



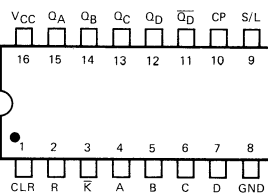
CONNECTION DIAGRAMS

Top Views

'LS194A

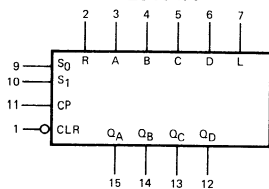


'LS195A

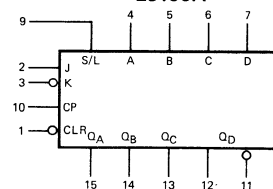


LOGIC SYMBOLS

'LS194A



'LS195A



V_{CC} = Pin 16
GND = Pin 8

Am25LS194A • Am25LS195A

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -440 μ A V _{IN} = V _{IH} or V _{IL}	MIL	2.5	3.4	Volts	
			COM'L	2.7	3.4		
V _{OL}	Output LOW Voltage	V _{CC} = MIN. V _{IN} = V _{IH} or V _{IL}	I _{OL} = 4mA		0.4	Volts	
			I _{OL} = 8mA		0.45		
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2			Volts	
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.5	Volts	
I _{IL}	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.4V			-0.4	mA	
I _{IH}	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			20	μ A	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 7.0V			0.1	mA	
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.	-15		-85	mA	
I _{CC}	Power Supply Current	V _{CC} = MAX.	LS194A (Note 4)		15	23	mA
			LS195A (Note 5)		14	21	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25 $^\circ$ C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Outputs open. Inputs A, B, C, D grounded. Inputs S₀, S₁, Clear, L, R, at 4.5V. Measured after a momentary ground, then 4.5V applied to clock.
 5. Outputs open. S/L grounded. A, B, C, D, J, K at 4.5V. Measured after applying a momentary ground then 4.5V to the clear followed by ground then 4.5V to clock.

3

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65 $^\circ$ C to +150 $^\circ$ C
Temperature (Ambient) Under Bias	-55 $^\circ$ C to +125 $^\circ$ C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30mA to +5.0mA

Am25LS/54LS/74LS194A/195A

Am54LS/74LS194A • Am54LS/74LS195A

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)

MIL' $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -400μA V _{IN} = V _{IH} or V _{IL}	Am74LS	2.7	3.4	Volts	
			Am54LS	2.5	3.4		
V _{OL}	Output LOW Voltage	V _{CC} = MIN. V _{IN} = V _{IH} or V _{IL}	All, I _{OL} = 4mA		0.4	Volts	
			74LS only, I _{OL} = 8mA		0.5		
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2		Volts		
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	Am54LS		0.7	Volts	
			Am74LS		0.8		
V _I	Input Clamp Voltage	V _{CC} = MIN., I _I = -18mA			-1.5	Volts	
I _{IL}	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.4V			-0.4	mA	
I _{IH}	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			20	μA	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 7.0V			0.1	mA	
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.	-15		-100	mA	
I _{CC}	Power Supply Current	V _{CC} = MAX.	LS194A (Note 4)		15	23	mA
			LS195A (Note 5)		14	21	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Outputs open. Inputs A, B, C, D grounded. Inputs S₀, S₁, Clear, L, R, at 4.5V. Measured after a momentary ground, then 4.5V applied to clock.
 5. Outputs open. S/L grounded. A, B, C, D, J, K at 4.5V. Measured after applying a momentary ground then 4.5V to the clear followed by ground then 4.5V to clock.

Am25LS194A • Am54LS/74LS194A

SWITCHING CHARACTERISTICS

(T_A = 25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	Clock to Output		13	21		14	22	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}	Clock to Output		12	18		17	26	ns	
t _{PHL}	Clear to Output		17	26		19	30	ns	
t _{pw}	Clock Pulse Width	17			20			ns	
t _{pw}	Clear Pulse Width	17			20			ns	
t _s	Mode Control Set-up Time	25			30			ns	
t _s	Data Input Set-up Time	16			20			ns	
t _s	Clear Recovery to Clock	20			25			ns	
t _h	Data Hold Time	0			0			ns	
f _{max} (Note 1)	Maximum Clock Frequency	35	55		25	36		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

Am25LS194A ONLY

SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	Clock to Output		31		36	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}	Clock to Output		28		32	ns	
t _{PHL}	Clear to Output		38		44	ns	
t _{pw}	Clock Pulse Width	26		30		ns	
t _{pw}	Clear Pulse Width	26		30		ns	
t _s	Mode Control Set-up Time	37		42		ns	
t _s	Data Input Set-up Time	25		29		ns	
t _s	Clear Recovery to Clock	30		35		ns	
t _h	Data Hold Time	4		5		ns	
f _{max} (Note 1)	Maximum Clock Frequency	26		23		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

Am25LS195A • Am54LS/74LS195
SWITCHING CHARACTERISTICS

(T_A = 25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	Clock to Output		13	21		14	22	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}	Clock to Output		12	18		17	26	ns	
t _{PHL}	Clear to Output		17	26		19	30	ns	
t _{pw}	Clock Pulse Width	16			16			ns	
t _{pw}	Clear Pulse Width	12			12			ns	
t _s	Mode Control Set-up Time	25			25			ns	
t _s	Data Input Set-up Time	15			15			ns	
t _s	Clear Recovery to Clock	20			25			ns	
t _h	Data Hold Time	0			0			ns	
t _R	Shift/Load Release Time Am54LS/74LS195A Only			0			0	ns	
f _{max} (Note 1)	Maximum Clock Frequency	35	55		30	39		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

Am25LS195A ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
		T _A = 0°C to +70°C V _{CC} = 5.0V ±5%		T _A = -55°C to +125°C V _{CC} = 5.0V ±10%			
t _{PLH}	Clock to Output		31		36	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}	Clock to Output		27		32	ns	
t _{PHL}	Clear to Output		38		44	ns	
t _{pw}	Clock Pulse Width	25		29		ns	
t _{pw}	Clear Pulse Width	20		23		ns	
t _s	Mode Control Set-up Time	37		42		ns	
t _s	Data Input Set-up Time	24		27		ns	
t _s	Clear Recovery to Clock	30		35		ns	
t _h	Data Hold Time	4		5		ns	
t _R	Shift/Load Release Time Am54LS/74LS195A Only		4		5	ns	
f _{max} (Note 1)	Maximum Clock Frequency	26		23		MHz	

* AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

'LS194A FUNCTION TABLE

FUNCTION	INPUTS						OUTPUTS							
	Clear	Mode		Serial		Parallel		Q _A Q _B Q _C Q _D						
		S ₁	S ₀	Left	Right	A	B	C	D	Q _A	Q _B	Q _C	Q _D	
Clear	L	X	X	X	X	X	X	X	X	L	L	L	L	
No Change	H	X	X	L	X	X	X	X	X	NC	NC	NC	NC	
Parallel Load	H	H	H	↑	X	X	D ₀	D ₁	D ₂	D ₃	D ₀	D ₁	D ₂	D ₃
Shift Right	H	L	H	↑	X	L	X	X	X	X	L	Q _A	Q _B	Q _C
Shift Left	H	H	L	↑	L	X	X	X	X	X	Q _B	Q _C	Q _D	L
Hold	H	L	L	X	X	X	X	X	X	X	NC	NC	NC	NC

H = HIGH
L = LOW
↑ = LOW-to-HIGH transition.
D_i = May be a HIGH or a LOW and the respective output will assume the same state.

X = Don't Care
NC = No Change

'LS195A FUNCTION TABLE

FUNCTION	INPUTS						OUTPUTS									
	Clear	Shift/Load	Clock	Serial		Parallel		Q _A Q _B Q _C Q _D Q̄ _D								
				J	K̄	A	B	C	D	Q _A	Q _B	Q _C	Q _D	Q̄ _D		
L	X	X	X	X	X	X	X	X	X	X	X	L	L	L	L	H
H	X	L	X	X	X	X	X	X	X	X	X	NC	NC	NC	NC	NC
H	X	H	X	X	X	X	X	X	X	X	X	NC	NC	NC	NC	NC
H	L	↑	X	X	D ₀	D ₁	D ₂	D ₃	D ₀	D ₁	D ₂	D ₃	D ₃	D ₃	D ₃	D ₃
H	H	↑	L	H	X	X	X	X	X	X	X	Q _A	Q _A	Q _B	Q _C	Q̄ _C
H	H	↑	L	L	X	X	X	X	X	X	X	L	Q _A	Q _B	Q _C	Q̄ _C
H	H	↑	H	H	X	X	X	X	X	X	X	H	Q _A	Q _B	Q _C	Q̄ _C
H	H	↑	H	L	X	X	X	X	X	X	X	Q̄ _A	Q _A	Q _B	Q _C	Q̄ _C

H = HIGH
L = LOW
↑ = LOW-to-HIGH transition.
D_i = May be a HIGH or a LOW and the respective output will assume the same state.

X = Don't Care
NC = No Change

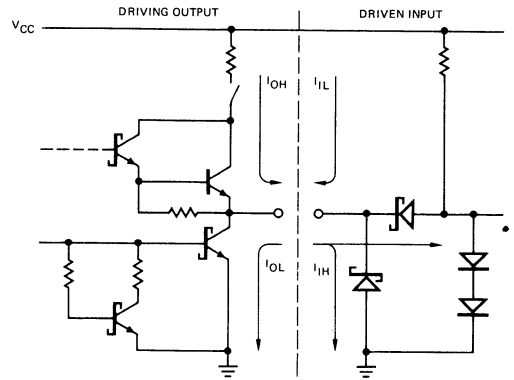
Notes: 1. If the J and K̄ inputs are tied together, the common line becomes a D-Type input to the first bit in the shift mode.
2. Linear feedback shift counters can be made by connecting the Q_D and Q̄_D outputs to the K̄ and J inputs, respectively.



DEFINITION OF FUNCTIONAL TERMS

- J, \bar{K}** The logic inputs used for controlling the Q_A flip-flop of the Am25LS195A register when S/L is HIGH.
- CLR** Clear. The asynchronous master reset input.
- CP** Clock pulse for the register. Enters data on the LOW-to-HIGH transition.
- S/L** Shift/Load. The input for selection of parallel or serial shifting for the Am25LS195A register. S/L LOW selects parallel entry.
- S_0, S_1** The mode select inputs of the Am25LS194A.
- A, B, C, D** The four parallel data inputs for the register.
- R** The serial input to the Q_A flip-flop of the Am25LS194A in the right shift mode.
- L** The serial input to the Q_D flip-flop of the Am25LS194A in the left shift mode.
- Q_A, Q_B, Q_C, Q_D** The four true outputs of the register.
- \bar{Q}_D** The complement output of the Q_D flip-flop. (Am25LS 195A only).

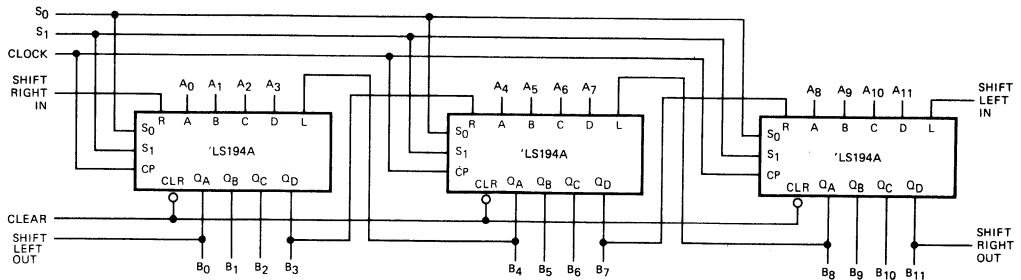
**Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**



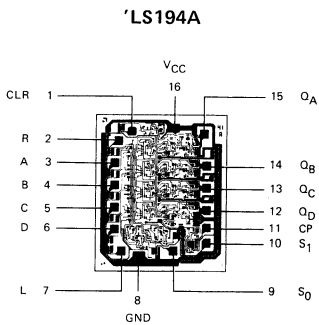
Note: Actual current flow direction shown.

APPLICATION

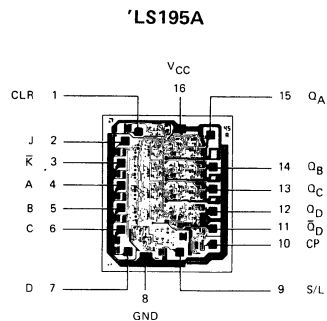
12-BIT SHIFT-LEFT, SHIFT-RIGHT, PARALLEL LOAD REGISTER



Metallization and Pad Layouts



DIE SIZE 0.067" X 0.080"



DIE SIZE 0.067" X 0.080"

Am25LS240 • Am54LS/74LS240

Octal Three-State Inverting Drivers

DISTINCTIVE CHARACTERISTICS

- Three-state outputs drive bus lines directly
- Hysteresis at inputs improve noise margin
- PNP inputs reduce D.C. loading on bus lines
- Data-to-output propagation delay times – 18ns MAX.
- Enable-to-output – 30ns MAX.
- Am25LS240 specified at 48mA output current
- 20 pin hermetic and molded DIP packages
- 100% product assurance testing to MIL-STD-883 requirements

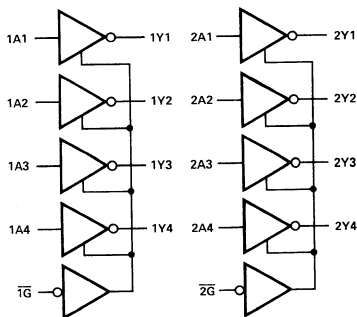
FUNCTIONAL DESCRIPTION

The 'LS240 is an octal inverting line driver fabricated using advanced low-power Schottky technology. The 20-pin package provides improved printed circuit board density for use in memory address and clock driver applications.

Three-state outputs are provided to drive bus lines directly. The Am25LS240 is specified at 48mA and 24mA output sink current, while the Am54/74LS240 is guaranteed at 12mA over the military range and 24mA over the commercial range. Four buffers are enabled from one common line and the other four from a second enable line.

Improved noise rejection and high fan-out are provided by input hysteresis and low current PNP inputs.

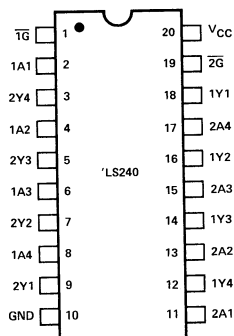
LOGIC DIAGRAM



INPUTS		OUTPUT
\bar{G}	A	Y
H	X	Z
L	H	L
L	L	H

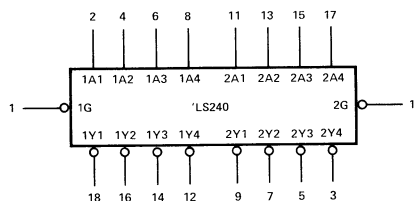
Note: All devices have input hysteresis.

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



VCC = Pin 20
GND = Pin 10

Am25LS240**ELECTRICAL CHARACTERISTICS**

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)**DC CHARACTERISTICS OVER OPERATING RANGE**

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	High-Level Output Voltage	$V_{CC} = \text{MIN.}, V_{IH} = 2.0\text{V}$ $I_{OH} = -3.0\text{mA}, V_{IL} = V_{IL\text{MAX.}}$	2.4	3.4		Volts	
		$V_{CC} = \text{MIN.},$ $V_{IL} = 0.5\text{V}$					
		MIL, $I_{OH} = -12\text{mA}$ COM'L, $I_{OH} = -15\text{mA}$	2.0				
V_{OL}	Low-Level Output Voltage	$V_{CC} = \text{MIN.}$	All $I_{OL} = 12\text{mA}$		0.25	0.4	Volts
			All $I_{OL} = 24\text{mA}$		0.35	0.5	
			COM'L $I_{OL} = 48\text{mA}$			0.55	
V_{IH}	High-Level Input Voltage	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Low-Level Input Voltage	COM'L			0.8	Volts	
		MIL			0.7		
V_{IK}	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_I = -18\text{mA}$			-1.5	Volts	
	Hysteresis ($V_{T+} - V_{T-}$)	$V_{CC} = \text{MIN.}$	0.2	0.4		Volts	
I_{OZH}	Off-State Output Current, High Level Voltage Applied	$V_{CC} = \text{MAX.}$ $V_{IH} = 2.0\text{V}$ $V_{IL} = V_{IL\text{MAX.}}$	$V_O = 2.7\text{V}$		20	μA	
I_{OZL}	Off-State Output Current, Low-Level Voltage Applied			$V_O = 0.4\text{V}$	-20		
I_I	Input Current at Maximum Input Voltage	$V_{CC} = \text{MAX.}, V_I = 7.0\text{V}$			0.1	mA	
I_{IH}	High-Level Input Current, Any Input	$V_{CC} \text{ MAX.}, V_{IH} = 2.7\text{V}$			20	μA	
I_{IL}	Low-Level Input Current	$V_{CC} = \text{MAX.}, V_{IL} = 0.4\text{V}$			-200	μA	
I_{SC}	Short Circuit Output Current (Note 3)	$V_{CC} = \text{MAX.}$	-50		-225	mA	
I_{CC}	Supply Current	$V_{CC} = \text{MAX.}$ Outputs open	All Outputs HIGH	13	23	mA	
			All Outputs LOW	26	44		
			Outputs at Hi-Z	29	50		

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under recommended operating conditions.
 2. All typical values are $V_{CC} = 5.0\text{V}, T_A = 25^\circ\text{C}$.
 3. Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

MAXIMUM RATINGS above which the useful life may be impaired

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current	150mA
DC Input Current	-30mA to +5.0mA

Am54LS/74LS240**ELECTRICAL CHARACTERISTICS**

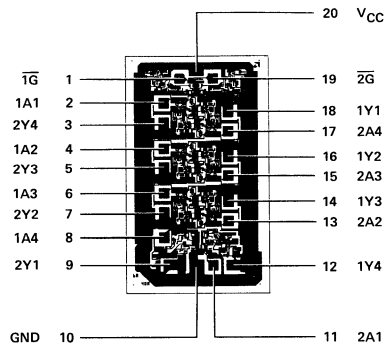
The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)
 MIL $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	High-Level Output Voltage	$V_{CC} = \text{MIN.}, V_{IH} = 2.0\text{V}$ $I_{OH} = -3.0\text{mA}, V_{IL} = V_{IL}\text{MAX.}$	2.4	3.4		Volts	
		$V_{CC} = \text{MIN.},$ $V_{IL} = 0.5\text{V}$	2.0				
		MIL, $I_{OH} = -12\text{mA}$ COM'L, $I_{OH} = -15\text{mA}$	2.0				
V_{OL}	Low-Level Output Voltage	$V_{CC} = \text{MIN.}$	All, $I_{OL} = 12\text{mA}$	0.25	0.4	Volts	
			COM'L, $I_{OL} = 24\text{mA}$		0.35		0.5
V_{IH}	High-Level Input Voltage	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Low-Level Input Voltage	COM'L MIL			0.8	Volts	
					0.7		
V_{IK}	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_I = -18\text{mA}$			-1.5	Volts	
	Hysteresis ($V_{T+} - V_{T-}$)	$V_{CC} = \text{MIN.}$	0.2	0.4		Volts	
I_{OZH}	Off-State Output Current, High Level Voltage Applied	$V_{CC} = \text{MAX.}$ $V_{IH} = 2.0\text{V}$ $V_{IL} = V_{IL}\text{MAX.}$	$V_O = 2.7\text{V}$		20	μA	
I_{OZL}	Off-State Output Current, Low-Level Voltage Applied			$V_O = 0.4\text{V}$			-20
I_I	Input Current at Maximum Input Voltage	$V_{CC} = \text{MAX.}, V_I = 7.0\text{V}$			0.1	mA	
I_{IH}	High-Level Input Current, Any Input	$V_{CC} \text{ MAX.}, V_{IH} = 2.7\text{V}$			20	μA	
I_{IL}	Low-Level Input Current	$V_{CC} = \text{MAX.}, V_{IL} = 0.4\text{V}$			-200	μA	
I_{SC}	Short Circuit Output Current (Note 3)	$V_{CC} = \text{MAX.}$	-50		-225	mA	
I_{CC}	Supply Current	$V_{CC} = \text{MAX.}$ Outputs open	All Outputs HIGH	13	23	mA	
			All Outputs LOW		26		44
			Outputs at Hi-Z		29		50

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under recommended operating conditions.
 2. All typical values are $V_{CC} = 5.0\text{V}, T_A = 25^\circ\text{C}$.
 3. Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

Metallization and Pad Layout

DIE SIZE 0.060" X 0.103"

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

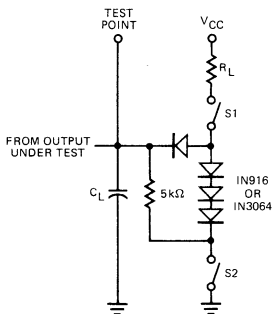
Parameters	Description	Am25LS240			Am54LS/74LS240			Units	Test Conditions (Notes 1–5)
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Propagation Delay Time, Low-to-High-Level Output		8.0	12		9.0	14	ns	$C_L = 45\text{pF}$ $R_L = 667\Omega$
t_{PHL}	Propagation Delay Time, High-to-Low-Level Output		12	16		12	18	ns	
t_{PZL}	Output Enable Time to Low Level		19	27		20	30	ns	
t_{PZH}	Output Enable Time to High Level		14	20		15	23	ns	
t_{PLZ}	Output Disable Time from Low Level		14	23		15	25	ns	$C_L = 5.0\text{pF}$ $R_L = 667\Omega$
t_{PHZ}	Output Disable Time from High Level		10	18		10	18	ns	

**Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE***

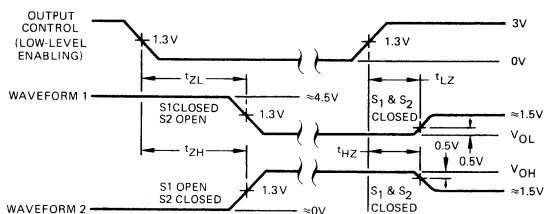
Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$			
t_{PLH}	Propagation Delay Time, Low-to-High-Level Output		16		19	ns	$C_L = 45\text{pF}$ $R_L = 667\Omega$
t_{PHL}	Propagation Delay Time, High-to-Low-Level Output		22		25	ns	
t_{PZL}	Output Enable Time to Low Level		37		42	ns	
t_{PZH}	Output Enable Time to High Level		27		31	ns	
t_{PLZ}	Output Disable Time from Low Level		31		36	ns	$C_L = 5.0\text{pF}$ $R_L = 667\Omega$
t_{PHZ}	Output Disable Time from High Level		25		28	ns	

* AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

**LOAD CIRCUIT FOR
THREE-STATE OUTPUTS**



**VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES, THREE-STATE OUTPUTS**



- Notes:
1. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
 2. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 3. In the examples above, the phase relationships between inputs and outputs have been chosen arbitrarily. $PRR \leq 1.0\text{MHz}$, $Z_{OUT} \approx 50\Omega$ and $t_r \leq 2.5\text{ns}$, $t_f \leq 2.5\text{ns}$.

Am25LS241 • Am54LS/74LS241 Am25LS244 • Am54LS/74LS244

Octal Three-State Buffers

DISTINCTIVE CHARACTERISTICS

- Three-state outputs drive bus lines directly
- Hysteresis at inputs improve noise margin
- PNP inputs reduce D.C. loading on bus lines
- Data-to-output propagation delay times – 18ns MAX.
- Enable-to-output – 30ns MAX.
- Am25LS241 and 244 specified at 48mA output current
- 20 pin hermetic and molded DIP packages
- 100% product assurance testing to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

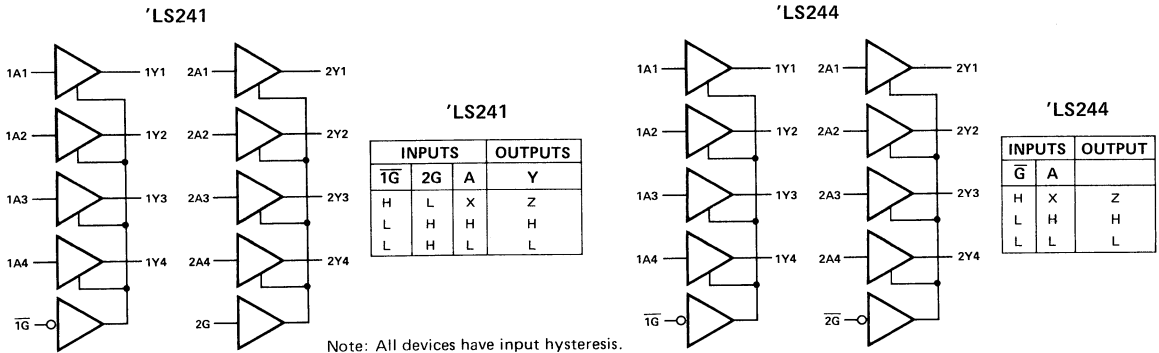
The 'LS241 and 'LS244 are octal buffers fabricated using advanced low-power Schottky technology. The 20-pin package provides improved printed circuit board density for use in memory address and clock driver applications.

Three-state outputs are provided to drive bus lines directly. The Am25LS241 and Am25LS244 are specified at 48mA and 24mA output sink current, while the Am54LS/74LS241 and Am54LS/74LS244 are guaranteed at 12mA over the military range and 24mA over the commercial range. Four buffers are enabled from one common line and the other four from a second enable line.

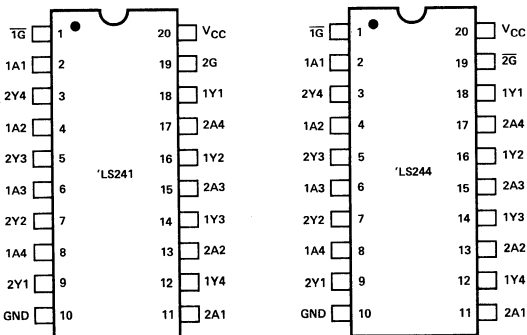
The 'LS241 has enable inputs of opposite polarity to allow use as a transceiver without overlap. The 'LS244 enables are of similar polarity for use as a unidirectional buffer in which both halves are enabled simultaneously.

Improved noise rejection and high fan-out are provided by input hysteresis and low current PNP inputs.

LOGIC DIAGRAMS

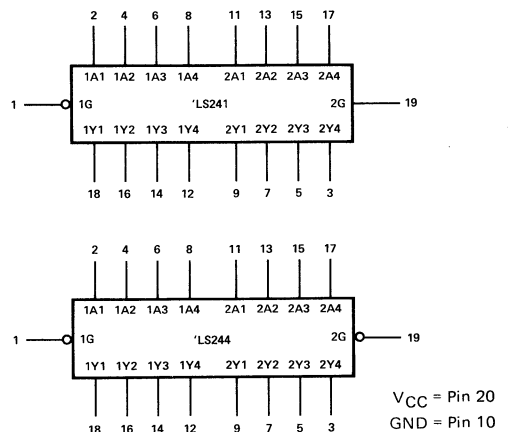


CONNECTION DIAGRAMS Top Views



Note: Pin 1 is marked for orientation.

LOGIC SYMBOLS



Am25LS241 • Am25LS244

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	High-Level Output Voltage	$V_{CC} = \text{MIN.}, V_{IH} = 2.0\text{V}$ $I_{OH} = -3.0\text{mA}, V_{IL} = V_{IL\text{MAX.}}$	2.4	3.4		Volts	
		$V_{CC} = \text{MIN.},$ $V_{IL} = 0.5\text{V}$	MIL, $I_{OH} = -12\text{mA}$ COM'L, $I_{OH} = -15\text{mA}$	2.0 2.0			
V_{OL}	Low-Level Output Voltage	$V_{CC} = \text{MIN.}$	All $I_{OL} = 12\text{mA}$		0.25	0.4	Volts
			All $I_{OL} = 24\text{mA}$		0.35	0.5	
			COM'L, $I_{OL} = 48\text{mA}$			0.55	
V_{IH}	High-Level Input Voltage	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Low-Level Input Voltage	COM'L			0.8	Volts	
		MIL			0.7		
V_{IK}	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_I = -18\text{mA}$			-1.5	Volts	
	Hysteresis ($V_{T+} - V_{T-}$)	$V_{CC} = \text{MIN.}$	0.2	0.4		Volts	
I_{OZH}	Off-State Output Current, High Level Voltage Applied	$V_{CC} = \text{MAX.}$ $V_{IH} = 2.0\text{V}$ $V_{IL} = V_{IL\text{MAX.}}$	$V_O = 2.7\text{V}$		20	μA	
I_{OZL}	Off-State Output Current, Low-Level Voltage Applied			$V_O = 0.4\text{V}$			-20
I_I	Input Current at Maximum Input Voltage	$V_{CC} = \text{MAX.}, V_I = 7.0\text{V}$			0.1	mA	
I_{IH}	High-Level Input Current, Any Input	$V_{CC} = \text{MAX.}, V_{IH} = 2.7\text{V}$			20	μA	
I_{IL}	Low-Level Input Current	$V_{CC} = \text{MAX.}, V_{IL} = 0.4\text{V}$			-200	μA	
I_{SC}	Short Circuit Output Current (Note 3)	$V_{CC} = \text{MAX.}$	-50		-225	mA	
I_{CC}	Supply Current	$V_{CC} = \text{MAX.}$ Outputs open	All Outputs HIGH		13	23	mA
			All Outputs LOW		27	46	
			Outputs at Hi-Z		32	54	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under recommended operating conditions.

2. All typical values are $V_{CC} = 5.0\text{V}, T_A = 25^\circ\text{C}$.

3. Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

MAXIMUM RATINGS

above which the useful life may be impaired

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current	150mA
DC Input Current	-30mA to +5.0mA

Am54LS/74LS241 • Am54LS/74LS244

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	High-Level Output Voltage	$V_{CC} = \text{MIN.}, V_{IH} = 2.0\text{V}$ $I_{OH} = -3.0\text{mA}, V_{IL} = V_{IL\text{MAX.}}$	2.4	3.4		Volts	
		$V_{CC} = \text{MIN.},$ $V_{IL} = 0.5\text{V}$	MIL, $I_{OH} = -12\text{mA}$ COM'L, $I_{OH} = -15\text{mA}$	2.0 2.0			
V_{OL}	Low-Level Output Voltage	$V_{CC} = \text{MIN.}$	All, $I_{OL} = 12\text{mA}$	0.25	0.4	Volts	
			COM'L, $I_{OL} = 24\text{mA}$		0.35		0.5
V_{IH}	High-Level Input Voltage	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Low-Level Input Voltage	COM'L			0.8	Volts	
		MIL			0.7		
V_{IK}	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_I = -18\text{mA}$			-1.5	Volts	
	Hysteresis ($V_{T+} - V_{T-}$)	$V_{CC} = \text{MIN.}$	0.2	0.4		Volts	
I_{OZH}	Off-State Output Current, High Level Voltage Applied	$V_{CC} = \text{MAX.}$ $V_{IH} = 2.0\text{V}$ $V_{IL} = V_{IL\text{MAX.}}$	$V_O = 2.7\text{V}$		20	μA	
I_{OZL}	Off-State Output Current, Low-Level Voltage Applied			$V_O = 0.4\text{V}$			-20
I_I	Input Current at Maximum Input Voltage	$V_{CC} = \text{MAX.}, V_I = 7.0\text{V}$			0.1	mA	
I_{IH}	High-Level Input Current, Any Input	$V_{CC} = \text{MAX.}, V_{IH} = 2.7\text{V}$			20	μA	
I_{IL}	Low-Level Input Current	$V_{CC} = \text{MAX.}, V_{IL} = 0.4\text{V}$			-200	μA	
I_{SC}	Short Circuit Output Current (Note 3)	$V_{CC} = \text{MAX.}$	-50		-225	mA	
I_{CC}	Supply Current	$V_{CC} = \text{MAX.}$ Outputs open	All Outputs HIGH		13	mA	
			All Outputs LOW		27		46
			Outputs at Hi-Z		32		54

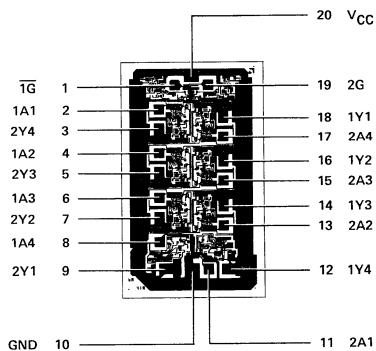
Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under recommended operating conditions.

2. All typical values are $V_{CC} = 5.0\text{V}, T_A = 25^\circ\text{C}$.

3. Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

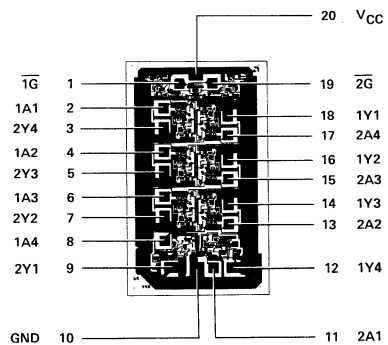
Metallization and Pad Layouts

'LS241



DIE SIZE 0.060" X 0.103"

'LS244



DIE SIZE 0.060" X 0.103"

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

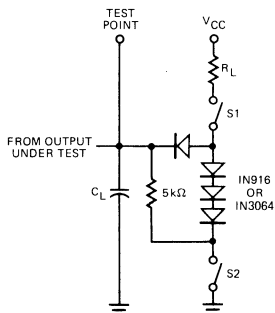
Parameters	Description	Am25LS241 Am25LS244			Am54LS/74LS241 Am54LS/74LS244			Units	Test Conditions (Notes 1-5)
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Propagation Delay Time, Low-to-High-Level Output		10	15		12	18	ns	$C_L = 45\text{pF}$ $R_L = 667\Omega$
t_{PHL}	Propagation Delay Time, High-to-Low-Level Output		12	18		12	18		
t_{PZL}	Output Enable Time to Low Level		20	30		20	30		
t_{PZH}	Output Enable Time to High Level		15	23		15	23		
t_{PLZ}	Output Disable Time from Low Level		15	25		15	25	ns	$C_L = 5.0\text{pF}$ $R_L = 667\Omega$
t_{PHZ}	Output Disable Time from High Level		10	18		10	18		

**Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE***

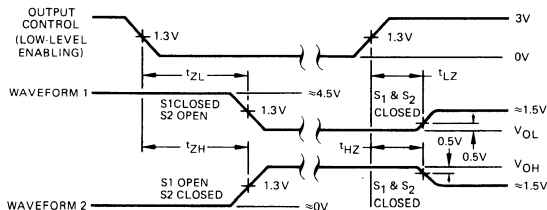
Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Propagation Delay Time, Low-to-High-Level Output	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$		ns	$C_L = 45\text{pF}$ $R_L = 667\Omega$
t_{PHL}	Propagation Delay Time, High-to-Low-Level Output		21		24		
t_{PZL}	Output Enable Time to Low Level		41		47		
t_{PZH}	Output Enable Time to High Level		31		47		
t_{PLZ}	Output Disable Time from Low Level		34		36	ns	$C_L = 5.0\text{pF}$ $R_L = 667\Omega$
t_{PHZ}	Output Disable Time from High Level		25		28		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

**LOAD CIRCUIT FOR
THREE-STATE OUTPUTS**



**VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES, THREE-STATE OUTPUTS**



- Notes:
1. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
 2. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 3. In the examples above, the phase relationships between inputs and outputs have been chosen arbitrarily.
 4. Pulse generator characteristics: $PRR \leq 1.0\text{MHz}$, $Z_{OUT} \approx 50\Omega$, $t_r \leq 15\text{ns}$, $t_f \leq 6\text{ns}$.
 5. When measuring t_{PLH} and t_{PHL} , switches S_1 and S_2 are closed.

Am25LS242 • Am54LS/74LS242

Am25LS243 • Am54LS/74LS243

Quad Bus Transceivers with Three-State Outputs

DISTINCTIVE CHARACTERISTICS

- Three-state outputs drive bus lines directly
- Hysteresis at inputs improve noise margin
- PNP inputs reduce D.C. loading on bus lines
- Data to output propagation delay times – 18ns MAX.
- Enable to output – 30ns MAX.
- Am25LS242 and Am25LS243 are specified at 48mA output current
- 100% product assurance testing to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

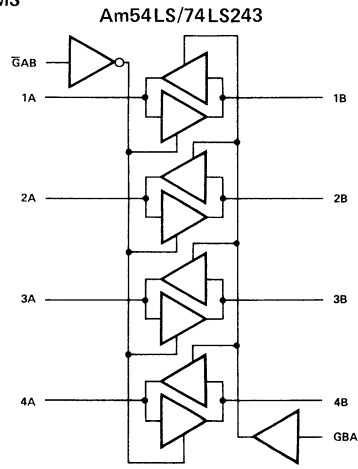
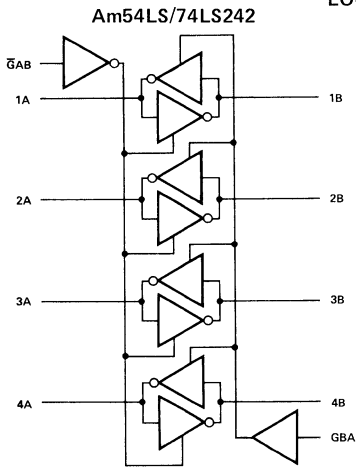
The 'LS242 and 'LS243 are quad bus transceivers designed for asynchronous two-way communications between data buses.

The 'LS242 and 'LS243 have the two 4-line data paths connected input-to-output on both sides to form an asynchronous transceiver/buffer with complementing enable inputs. The 'LS242 is inverting, while the 'LS243 presents non-inverting data at the outputs.

Three-state outputs are provided to drive bus lines directly. The Am25LS242 and Am25LS243 are specified at 48mA and 24mA output sink current, while the Am54/74LS242 and 243 are guaranteed at 12mA over the military range and 24mA over the commercial range.

Improved noise rejection and high fan-out are provided by input hysteresis and low current PNP inputs.

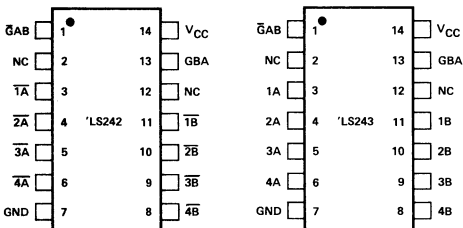
LOGIC DIAGRAMS



Note: All devices have input hysteresis.

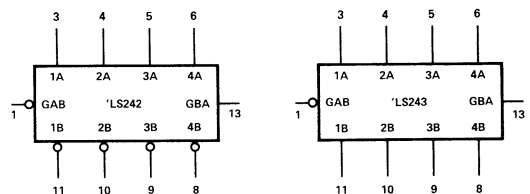
CONNECTION DIAGRAMS

Top Views



Note: Pin 1 is marked for orientation

LOGIC SYMBOLS



VCC = Pin 14
GND = Pin 7

3

Am25LS242 • Am25LS243**ELECTRICAL CHARACTERISTICS**

The Following Conditions Apply unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)**DC CHARACTERISTICS OVER OPERATING RANGE**

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	High-Level Output Voltage	$V_{CC} = \text{MIN.}, V_{IH} = 2.0\text{V}$ $I_{OH} = -3.0\text{mA}, V_{IL} = V_{IL\text{MAX.}}$	2.4	3.4		Volts	
		$V_{CC} = \text{MIN.},$ $V_{IL} = 0.5\text{V}$	2.0				
		MIL, $I_{OH} = -12\text{mA}$ COM'L, $I_{OH} = -15\text{mA}$	2.0				
V_{OL}	Low-Level Output Voltage	$V_{CC} = \text{MIN.}$	All $I_{OL} = 12\text{mA}$	0.25	0.4	Volts	
			All $I_{OL} = 24\text{mA}$	0.35	0.5		
			COM'L, $I_{OL} = 48\text{mA}$		0.55		
V_{IH}	High-Level Input Voltage	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Low-Level Input Voltage	COM'L			0.8	Volts	
		MIL			0.7		
V_{IK}	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_I = -18\text{mA}$			-1.5	Volts	
	Hysteresis ($V_{T+} - V_{T-}$)	$V_{CC} = \text{MIN.}$	0.2	0.4		Volts	
I_{OZH}	Off-State Output Current, High Level Voltage Applied	$V_{CC} = \text{MAX.}$ $V_{IH} = 2.0\text{V}$ $V_{IL} = V_{IL\text{MAX.}}$	$V_O = 2.7\text{V}$		20	μA	
I_{OZL}	Off-State Output Current, Low-Level Voltage Applied			$V_O = 0.4\text{V}$	-20		
I_I	Input Current at Maximum Input Voltage	$V_{CC} = \text{MAX.}, V_I = 7.0\text{V}$			0.1	mA	
I_{IH}	High-Level Input Current, Any Input	$V_{CC} = \text{MAX.}, V_{IH} = 2.7\text{V}$			20	μA	
I_{IL}	Low-Level Input Current	$V_{CC} = \text{MAX.}, V_{IL} = 0.4\text{V}$			-200	μA	
I_{SC}	Short Circuit Output Current (Note 3)	$V_{CC} = \text{MAX.}$	-50		-225	mA	
I_{CC}	Supply Current	$V_{CC} = \text{MAX.}$ Outputs open (Note 4)	All Outputs HIGH	'LS242, 'LS243	22	38	mA
			All Outputs LOW	'LS242, 'LS243	29	50	
			Outputs at Hi-Z	'LS242	29	50	
			'LS243	32	54		

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under recommended operating conditions.

2. All typical values are $V_{CC} = 5.0\text{V}, T_A = 25^\circ\text{C}$.

3. Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

4. For 'LS242 and 'LS243 I_{CC} is measured with transceivers enabled in one direction only, or with all transceivers disabled.**MAXIMUM RATINGS** above which the useful life may be impaired

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current	150mA
DC Input Current	-30mA to +5.0mA

Am54LS/74LS242 • Am54LS/74LS243

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	High-Level Output Voltage	$V_{CC} = \text{MIN.}, V_{IH} = 2.0\text{V}$ $I_{OH} = -3.0\text{mA}, V_{IL} = V_{IL\text{MAX.}}$	2.4	3.4		Volts	
		$V_{CC} = \text{MIN.},$ $V_{IL} = 0.5\text{V}$	MIL, $I_{OH} = -12\text{mA}$ COM'L, $I_{OH} = -15\text{mA}$	2.0 2.0			
V_{OL}	Low-Level Output Voltage	$V_{CC} = \text{MIN.}$	All, $I_{OL} = 12\text{mA}$	0.25	0.4	Volts	
			COM'L, $I_{OL} = 24\text{mA}$		0.35		0.5
V_{IH}	High-Level Input Voltage	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Low-Level Input Voltage	COM'L			0.8	Volts	
		MIL			0.7		
V_{IK}	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_I = -18\text{mA}$			-1.5	Volts	
	Hysteresis ($V_{T+} - V_{T-}$)	$V_{CC} = \text{MIN.}$	0.2	0.4		Volts	
I_{OZH}	Off-State Output Current, High Level Voltage Applied	$V_{CC} = \text{MAX.}$ $V_{IH} = 2.0\text{V}$ $V_{IL} = V_{IL\text{MAX.}}$	$V_O = 2.7\text{V}$		20	μA	
I_{OZL}	Off-State Output Current, Low-Level Voltage Applied			$V_O = 0.4\text{V}$			-20
I_I	Input Current at Maximum Input Voltage	$V_{CC} = \text{MAX.}, V_I = 7.0\text{V}$			0.1	mA	
I_{IH}	High-Level Input Current, Any Input	$V_{CC} \text{ MAX.}, V_{IH} = 2.7\text{V}$			20	μA	
I_{IL}	Low-Level Input Current	$V_{CC} = \text{MAX.}, V_{IL} = 0.4\text{V}$			-200	μA	
I_{SC}	Short Circuit Output Current (Note 3)	$V_{CC} = \text{MAX.}$	-50		-225	mA	
I_{CC}	Supply Current	$V_{CC} = \text{MAX.}$ Outputs open (Note 4)	All Outputs HIGH	'LS242, 'LS243	22	38	mA
			All Outputs LOW	'LS242, 'LS243	29	50	
			Outputs at Hi-Z	'LS242 'LS243	29 32	50 54	

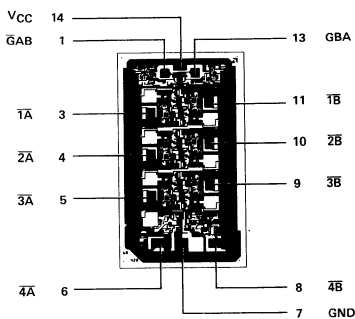
Notes: 1. For conditions shown as MIN' or MAX., use the appropriate value specified under recommended operating conditions.

2. All typical values are $V_{CC} = 5.0\text{V}, T_A = 25^\circ\text{C}$.

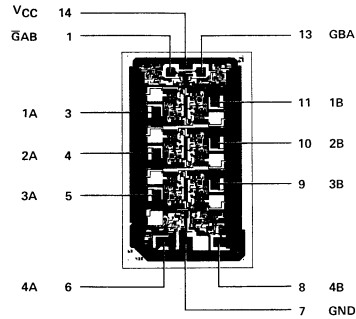
3. Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

4. For 'LS242 and 'LS243 I_{CC} is measured with transceivers enabled in one direction only, or with all transceivers disabled.

Metallization and Pad Layouts



DIE SIZE 0.060" x 0.103"



DIE SIZE 0.060" x 0.103"

Am25LS242 • Am54LS/74LS242
SWITCHING CHARACTERISTICS $(T_A = +25^\circ\text{C}, V_{CC} = 5.0\text{V})$

Parameters	Description	Am25LS242			Am54LS/74LS242			Units	Test Conditions (Notes 1–5)
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Propagation Delay Time, Low-to-High-Level Output		8.0	12		9.0	14	ns	$C_L = 45\text{pF}$ $R_L = 667\Omega$
t_{PHL}	Propagation Delay Time, High-to-Low-Level Output		12	16		12	18	ns	
t_{PZL}	Output Enable Time to Low Level		20	30		20	30	ns	
t_{PZH}	Output Enable Time to High Level		15	23		15	23	ns	
t_{PLZ}	Output Disable Time from Low Level		15	25		15	25	ns	$C_L = 5.0\text{pF}$ $R_L = 667\Omega$
t_{PHZ}	Output Disable Time from High Level		10	18		10	18	ns	

Am25LS242 ONLY
SWITCHING CHARACTERISTICS
OVER OPERATION RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$			
t_{PLH}	Propagation Delay Time, Low-to-High-Level Output		16		19	ns	$C_L = 45\text{pF}$ $R_L = 667\Omega$
t_{PHL}	Propagation Delay Time, High-to-Low-Level Output		22		25	ns	
t_{PZL}	Output Enable Time to Low Level		37		42	ns	
t_{PZH}	Output Enable Time to High Level		29		33	ns	
t_{PLZ}	Output Disable Time from Low Level		33		38	ns	$C_L = 5.0\text{pF}$ $R_L = 667\Omega$
t_{PHZ}	Output Disable Time from High Level		25		28	ns	

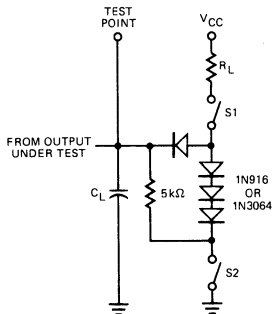
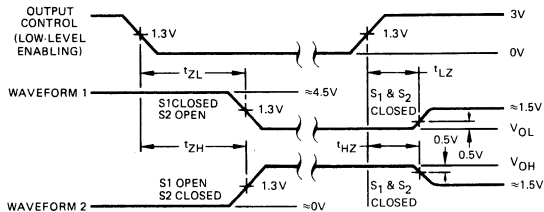
Am25LS243 • Am54LS/74LS243
SWITCHING CHARACTERISTICS $(T_A = +25^\circ\text{C}, V_{CC} = 5.0\text{V})$

Parameters	Description	Am25LS243			Am54LS/74LS243			Units	Test Conditions (Notes 1–5)
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Propagation Delay Time, Low-to-High-Level Output		10	15		12	18	ns	$C_L = 45\text{pF}$ $R_L = 667\Omega$
t_{PHL}	Propagation Delay Time, High-to-Low-Level Output		12	18		12	18	ns	
t_{PZL}	Output Enable Time to Low Level		20	30		20	30	ns	
t_{PZH}	Output Enable Time to High Level		15	23		15	23	ns	
t_{PLZ}	Output Disable Time from Low Level		15	25		15	25	ns	$C_L = 5.0\text{pF}$ $R_L = 667\Omega$
t_{PHZ}	Output Disable Time from High Level		10	18		10	18	ns	

Am25LS243 ONLY
SWITCHING CHARACTERISTICS
OVER OPERATION RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$			
t_{PLH}	Propagation Delay Time, Low-to-High-Level Output		21		24	ns	$C_L = 45\text{pF}$ $R_L = 667\Omega$
t_{PHL}	Propagation Delay Time, High-to-Low-Level Output		25		28	ns	
t_{PZL}	Output Enable Time to Low Level		41		47	ns	
t_{PZH}	Output Enable Time to High Level		33		49	ns	
t_{PLZ}	Output Disable Time from Low Level		36		38	ns	$C_L = 5.0\text{pF}$ $R_L = 667\Omega$
t_{PHZ}	Output Disable Time from High Level		25		28	ns	

SWITCHING CHARACTERISTICS TEST CONDITIONS

LOAD CIRCUIT FOR
THREE-STATE OUTPUTSVOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES, THREE-STATE OUTPUTS

- Notes:
1. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
 2. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 3. In the examples above, the phase relationships between inputs and outputs have been chosen arbitrarily.
 4. Pulse generator characteristics: $PRR \leq 1\text{MHz}$, $Z_{OUT} \approx 50\Omega$, $t_r \leq 15\text{ns}$, $t_f \leq 6\text{ns}$.
 5. When measuring t_{PLH} and t_{PHL} , switches S_1 and S_2 are closed.

3

FUNCTION TABLES

Am54LS/74LS242

CONTROL INPUTS		DATA OUTPUTS	
$\overline{\text{GAB}}$	GBA	A	B
H	H	$\overline{\text{O}}$	I
L	H	*	*
H	L	ISOLATED	
L	L	I	$\overline{\text{O}}$

I = Input

H = HIGH

O = Output

L = LOW

 $\overline{\text{O}}$ = Inverting Output

Am54LS/74LS243

CONTROL INPUTS		DATA OUTPUTS	
$\overline{\text{GAB}}$	GBA	A	B
H	H	O	I
L	H	*	*
H	L	ISOLATED	
L	L	I	O

*Possible destructive oscillation may occur if the transceivers are enable in both directions at once.

Am54LS/74LS245

Octal Bus Transceiver

Advanced Micro Devices has no current plans to manufacture this product. See the Am8304 for a recommended improved Octal Bus Transceiver.

Am25LS251 • Am54LS/74LS251

Eight-Input Multiplexers

Am25LS251 • Am54LS/74LS251 data is combined with the Am25LS151.

See Am25LS151 data sheet for full information.

FUNCTIONAL DESCRIPTION

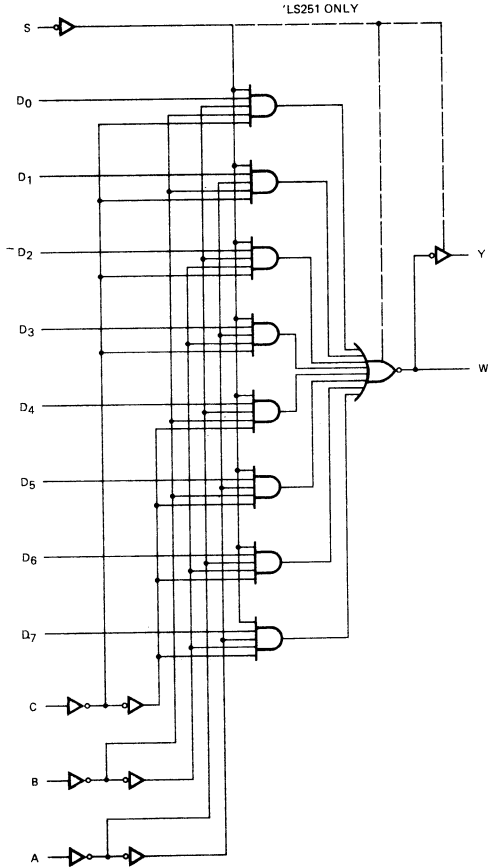
The Am25LS151 and the Am25LS251 are eight-input multiplexers that switch one of eight inputs onto the inverting and non-inverting outputs under the control of a three-bit select code. The inverting output W is one gate delay faster than the non-inverting output Y.

The Am25LS251 provides an active-LOW strobe. When the strobe is HIGH, the inverting output (W) is HIGH and the non-inverting output (Y) is LOW.

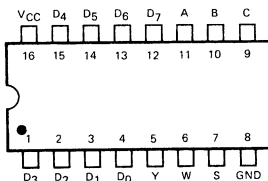
The Am25LS251 features a three-state output for data bus organization. The active-LOW strobe, or "output control" applies to both the inverting and non-inverting output. When the output control is HIGH, the outputs are in the high-impedance state. When the output control is LOW, the active pull-up output is enabled.

The Am54LS/74LS251 is a standard performance version of the Am25LS251. See appropriate electrical characteristics tables for detailed Am25LS improvements.

LOGIC DIAGRAM

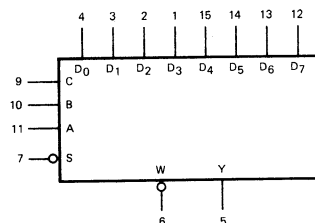


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



VCC = Pin 16
GND = Pin 8

Am25LS253 • Am54LS/74LS253

Dual 4-Line to 1-Line Data Selectors/Multiplexers

Am25LS253 • Am54LS/74LS253 data is combined with the Am25LS153.

See Am25LS153 data sheet for full information

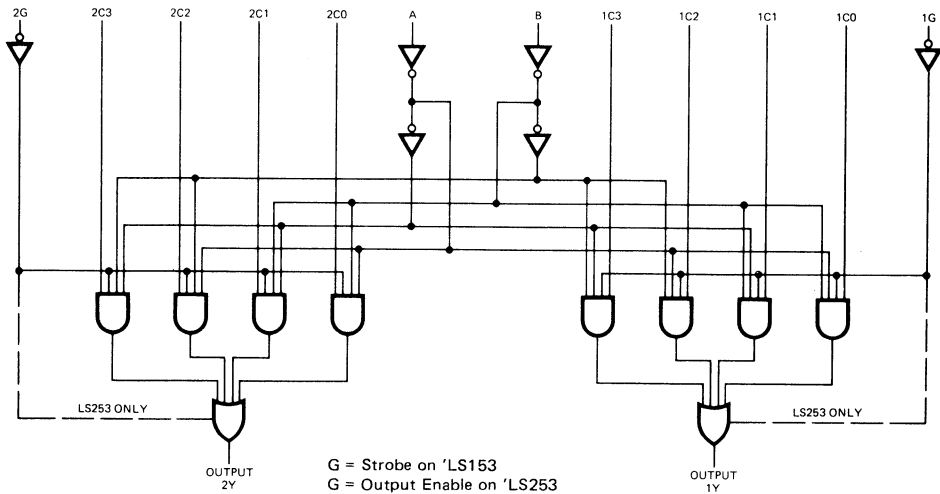
FUNCTIONAL DESCRIPTION

These dual four-input multiplexers provide the digital equivalent of a two-pole, four position switch with the position of both switches set by the logic levels supplied to the select inputs A and B. Each section of the Am25LS153 has a separate active-LOW enable (strobe) input that forces the output of that section LOW when a HIGH level is applied regardless of the other inputs.

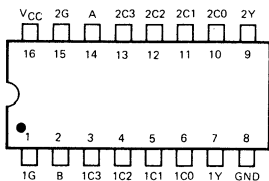
The Am25LS253 features a three-state output to interface with bus-organized systems. Each section of the Am25LS253 has a separate active-LOW output control that disables the output driver (high-impedance state) of that section when a HIGH logic level is applied regardless of the other inputs.

The Am54LS/74LS153 and 253 are standard performance versions of the Am25LS153 and 253. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAM

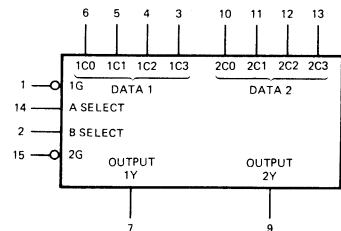


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



VCC = Pin 16
GND = Pin 8

Am25LS257 • Am54LS/74LS257

Am25LS258 • Am54LS/74LS258

Quaduple 2-Line To 1-Line Data Selectors/Multiplexers With 3-State Outputs

DISTINCTIVE CHARACTERISTICS

- Three-state outputs
- Pin-outs identical to standard TTL 'LS157 and 'LS158 devices
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL}
 - Twice the fan-out over military range
 - 440 μ A source current
- 100% product assurance screening to MIL-STD-883 requirements

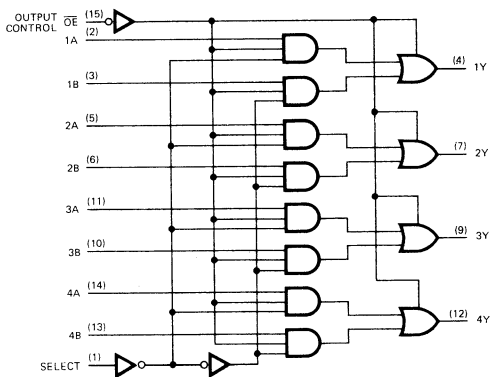
FUNCTIONAL DESCRIPTION

The 2-line to 1-line data selector multiplexer can be used to transfer data to a common data bus directly by using the three-state capability of the device. With the output control (OE) HIGH, the four outputs of the data selector are in the high impedance state. With the output control LOW, the selected four bits (A or B inputs) are bussed onto the four data lines.

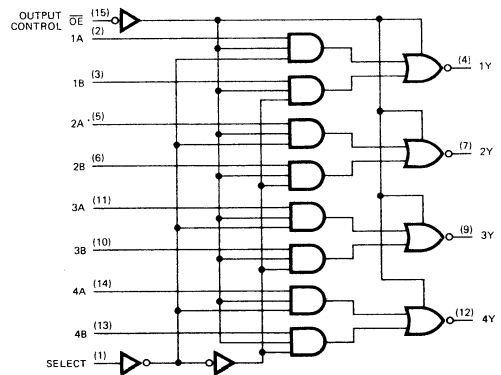
The Am54LS/74LS257 and 258 are standard performance versions of the Am25LS257 and 258. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAMS

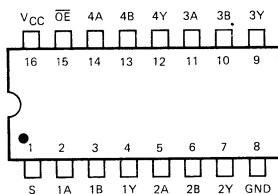
'LS257



'LS258



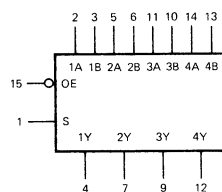
CONNECTION DIAGRAM
Top View



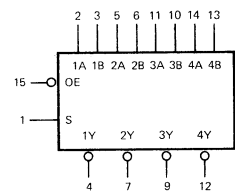
Note: Pin 1 is marked for orientation.

LOGIC SYMBOLS

'LS257



'LS258



VCC = Pin 16
GND = Pin 8

3

Am25LS/54LS/74LS257/258

Am25LS257 • Am25LS258

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH}$ or V_{IL}	MIL, $I_{OH} = -1\text{mA}$	2.4	3.4	Volts	
			COM'L, $I_{OH} = -2.6\text{mA}$	2.4	3.2		
V_{OL}	Output LOW Voltage		$I_{OL} = 4\text{mA}$		0.4	Volts	
			$I_{OL} = 8\text{mA}$		0.45		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	S, \overline{OE}		-0.36	mA	
			Others		-0.4		
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	S, \overline{OE}		20	μA	
			Others		20		
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$	S, \overline{OE}		0.1	mA	
			Others		0.1		
I_{OZ}	Off-State (HIGH Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 2.4\text{V}$		20	μA	
			$V_O = 0.4\text{V}$		-20		
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$ (Note 4)	All Outputs HIGH	LS257	6.3	10.0	mA
			All Outputs LOW	LS258	4.3	8.0	mA
				LS257	8.2	13.5	
			All Outputs OFF	LS258	6.1	11.0	mA
				LS257	9.7	15.3	
			LS258	7.2	11.2		

- Notes: 1. For conditions shown as MIN. or MAX. use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time and duration of the short circuit test should not exceed one second.
 4. I_{CC} is measured with all outputs open and all possible inputs grounded while achieving the stated output conditions.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5 V to +7.0 V
DC Voltage Applied to Outputs for High Output State	-0.5 V to V_{CC} max.
DC Input Voltage	-0.5 V to +7.0 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

Am54LS/74LS257 • Am54LS/74LS258

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\%$	(MIN. = 4.75V MAX. = 5.25V)
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\%$	(MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH}$ or V_{IL}	54LS, $I_{OH} = -1\text{mA}$	2.4	3.4	Volts	
			74LS, $I_{OH} = -2.6\text{mA}$	2.4	3.2		
V_{OL}	Output LOW Voltage				0.4	Volts	
					0.5		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2		Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	54LS 74LS		0.7 0.8	Volts	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	S Others		-0.8 -0.4	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	S Others		40 20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$	S Others		0.2 0.1	mA	
I_{OZ}	Off-State (HIGH Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 2.4\text{V}$ $V_O = 0.4\text{V}$		20 -20	μA	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15	-100	mA	
I_{CC}	Power Supply Current	All Outputs HIGH	$V_{CC} = \text{MAX.}$ (Note 4)	LS257	5.9	10	mA
				LS258	4.1	8	
		All Outputs LOW		LS257	9.2	16	mA
				LS258	6.2	11	
		All Outputs OFF		LS257	10	17	mA
				LS258	7.0	12	

3

- Notes: 1. For conditions shown as MIN. or MAX. use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time and duration of the short circuit test should not exceed one second.
 4. I_{CC} is measured with all outputs open and all possible inputs grounded while achieving the stated output conditions.

Am25LS/54LS/74LS257/258

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description		Am25LS			Am54LS/74LS			Units	Test Conditions
			Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Data to Output	LS257		8	12		12	18	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
		LS258		6	12		12	18		
t_{PHL}	Data to Output	LS257		8	12		12	18	ns	
		LS258		7	12		12	18		
t_{PLH}	Select to Output	LS257		14	21		14	21	ns	
		LS258		14	21		14	21		
t_{PHL}	Select to Output	LS257		14	21		14	21	ns	
		LS258		14	21		14	21		
t_{ZH}	Control to Output			13	20		20	30	ns	
t_{ZL}				13	20		20	30		
t_{HZ}	Control to Output			12	20		14	21	ns	
t_{LZ}				13	20		14	21		

Am25LS ONLY SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description		Am25LS COM'L		Am25LS MIL		Units	Test Conditions
			Min.	Max.	Min.	Max.		
			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$			
			$V_{CC} = 5.0\text{V} \pm 5\%$		$V_{CC} = 5.0\text{V} \pm 10\%$			
t_{PLH}	Data to Output	LS257		20		23	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
		LS258		20		23		
t_{PHL}	Data to Output	LS257		20		23	ns	
		LS258		20		23		
t_{PLH}	Select to Output	LS257		31		36	ns	
		LS258		31		36		
t_{PHL}	Select to Output	LS257		31		36	ns	
		LS258		31		36		
t_{ZH}	Control to Output			30		35	ns	
t_{ZL}				30		35		
t_{HZ}	Control to Output			26		30	ns	
t_{LZ}				26		30		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

1A, 2A, 3A, 4A The data inputs for the 4-bits of the A word.

1B, 2B, 3B, 4B The data inputs for the 4-bits of the B word.

1Y, 2Y, 3Y, 4Y The four outputs of the multiplexer.

\overline{OE} Output Control When the output control is HIGH, the four outputs are in the high impedance state. When the output control is LOW, the selected A or B input is present at the output.

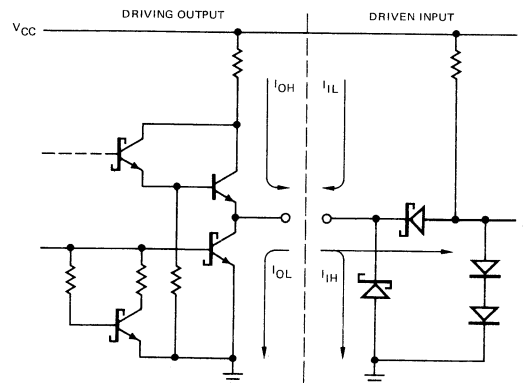
S Select When the select input is LOW, the A word is present at the output. When the select input is HIGH, the B word is present at the output.

FUNCTION TABLE

INPUTS				OUTPUTS	
Output Control	Select	A	B	'LS257	'LS258
H	X	X	X	Z	Z
L	L	L	X	L	H
L	L	H	X	H	L
L	H	X	L	L	H
L	H	X	H	H	L

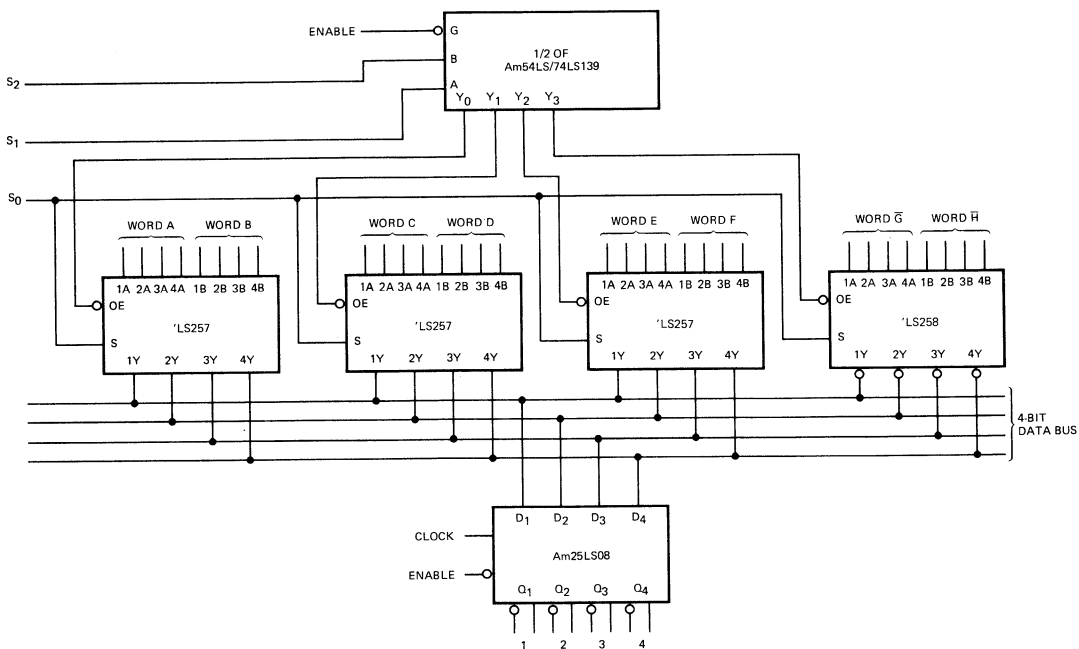
H = HIGH L = LOW X = Don't Care Z = High Impedance

Am25LS • Am54LS/74LS LOW-POWER SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



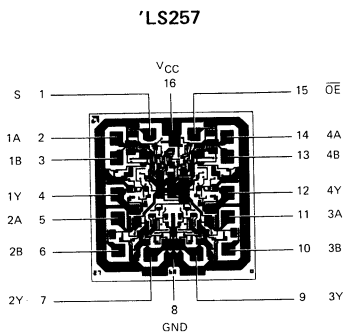
Note: Actual current flow direction shown.

APPLICATION

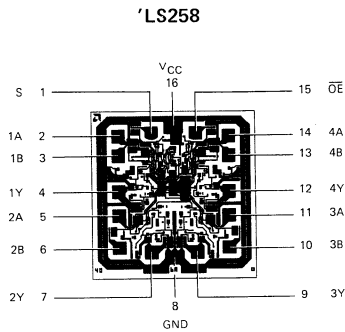


8-Word, 4-Bit Multiplexer

Metallization and Pad Layout



DIE SIZE 0.057" X 0.057"



DIE SIZE 0.057" X 0.057"

Am25LS273B • Am54LS/74LS273B

8-Bit Register with Clear

DISTINCTIVE CHARACTERISTICS

- Eight-bit, high-speed parallel registers
- Buffered outputs to eliminate output commutation
- Positive edge-triggered D-type flip-flops
- Common clock and common clear
- Am25LS devices offer the following improvements over Am54/74LS
 - 50mV lower V_{OL} at $I_{OL} = 8\text{mA}$
 - Twice the fan-out over military range
 - 440 μA source current at HIGH output
- 100% product assurance screening to MIL-STD-883 requirements

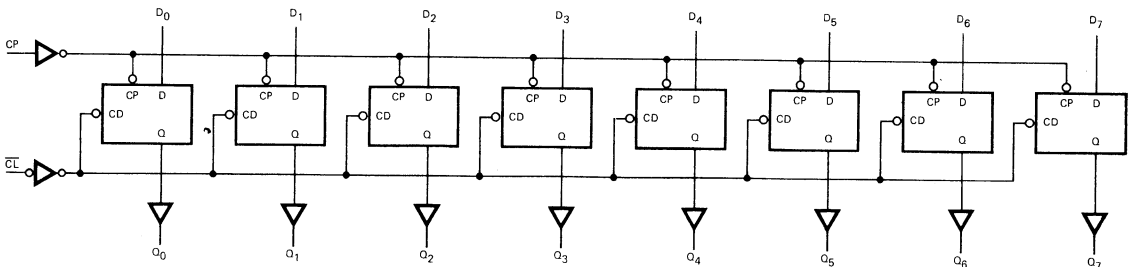
FUNCTIONAL DESCRIPTION

The Am25LS273B and the Am54LS/74LS273B are eight-bit registers built using Advanced Low-Power Schottky Technology. These registers consist of D-type flip-flops with a buffer common clock and an asynchronous active LOW buffered common clear.

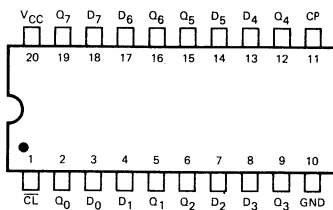
When the clear input is LOW, the Q outputs are LOW, independent of the other inputs. Information meeting the set-up and hold time requirements of the D inputs is transferred to the Q outputs on the LOW-to-HIGH transition of the clock input. These devices are supplied in the 20-pin space saving package featuring 0.3-inch centers between rows of leads.

Note: The B designation identifies buffered output versions provided to eliminate output commutation.

LOGIC DIAGRAM

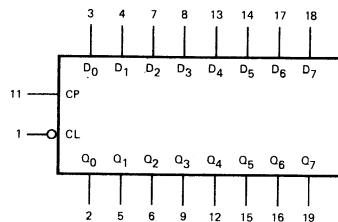


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 20

GND = Pin 10

Am25LS273B

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 VMIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.6	3.4	Volts
			COM'L	2.7	3.4	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.4	Volts
			$I_{OL} = 8.0\text{mA}$		0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.36	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		17	27	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. All outputs open and 4.5 V applied to the data and clear input. Measured after a momentary ground, then 4.5 V applied to the clock input.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5 V to +7.0 V
DC Voltage Applied to Outputs for High Output State	-0.5 V to + V_{CC} max.
DC Input Voltage	-0.5 V to +7.0 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 V
 MIL $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}$ $V_{IN} = V_{IH}$ or V_{IL}	MIL	2.5	3.4	Volts
			COM'L	2.7	3.4	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	All, $I_{OL} = 4.0\text{mA}$		0.4	Volts
			74LS only, $I_{OL} = 8.0\text{mA}$		0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.4	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-100	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		17	27	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. All outputs open and 4.5 V applied to the data and clear input. Measured after a momentary ground, then 4.5 V applied to the clock input.

DEFINITION OF FUNCTIONAL TERMS

- D_i The D flip-flop data inputs.
 $\overline{\text{CL}}$ Clear. When the clear is LOW, the Q_i outputs are LOW, regardless of the other inputs. When the clear is HIGH, data can be entered in the register.
 CP Clock pulse for the register. Enters data on the positive transition.
 Q_i The TRUE register outputs.

FUNCTION TABLE

INPUTS			OUTPUT
Clear	Clock	D_i	Q_i
L	X	X	L
H	L	X	NC
H	H	X	NC
H	\uparrow	L	L
H	\uparrow	H	H

H = HIGH
 L = LOW
 \uparrow = LOW-to-HIGH Transition

X = Don't Care
 NC = No Change

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	Clock to Output		21	32		21	32	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			26	38		26	38		
t _{PHL}	Clear to Output		28	39		28	39		
t _{pw}	Clock Pulse Width	HIGH	20		20				
		LOW	25		25				
t _{pw}	Clear Pulse Width	25			25				
t _s	Data Set-up	20			20				
t _h	Data Hold	10			10				
t _s	Set-up, Clear Recovery (In-Active) to Clock	25			25				
f _{max} (Note 1)	Maximum Clock Frequency	30	40		30			MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

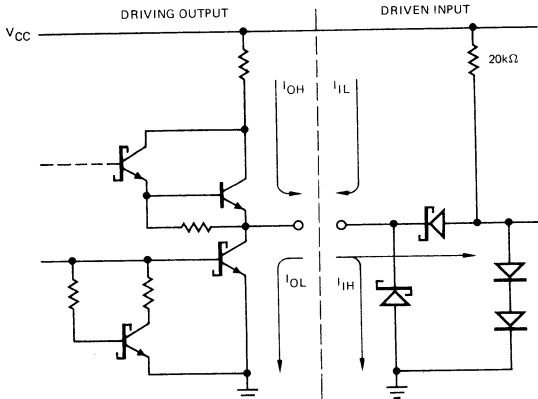
Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	Clock to Output		36		40	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			49		60		
t _{PHL}	Clear to Output		50		60		
t _{pw}	Clock Pulse Width	HIGH	25	30			
		LOW	30	35			
t _{pw}	Clear Pulse Width	25		25			
t _s	Data Set-up	20		20			
t _h	Data Hold	12		15			
t _s	Set-up, Clear Recovery (In-Active) to Clock	25		25			
f _{max} (Note 1)	Maximum Clock Frequency	25		20		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

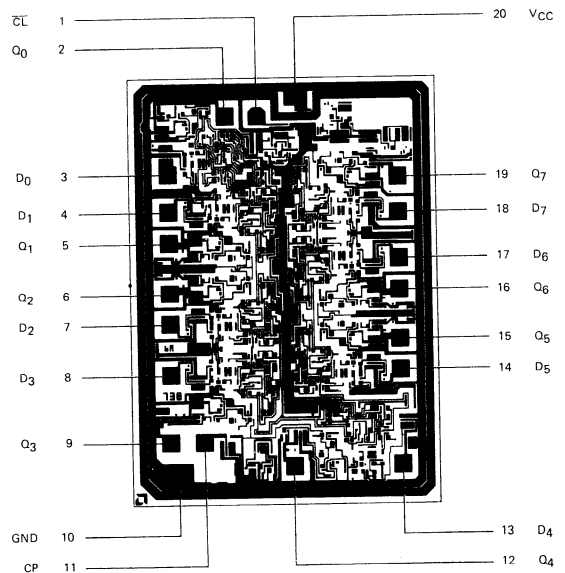
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Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

Metallization and Pad Layout

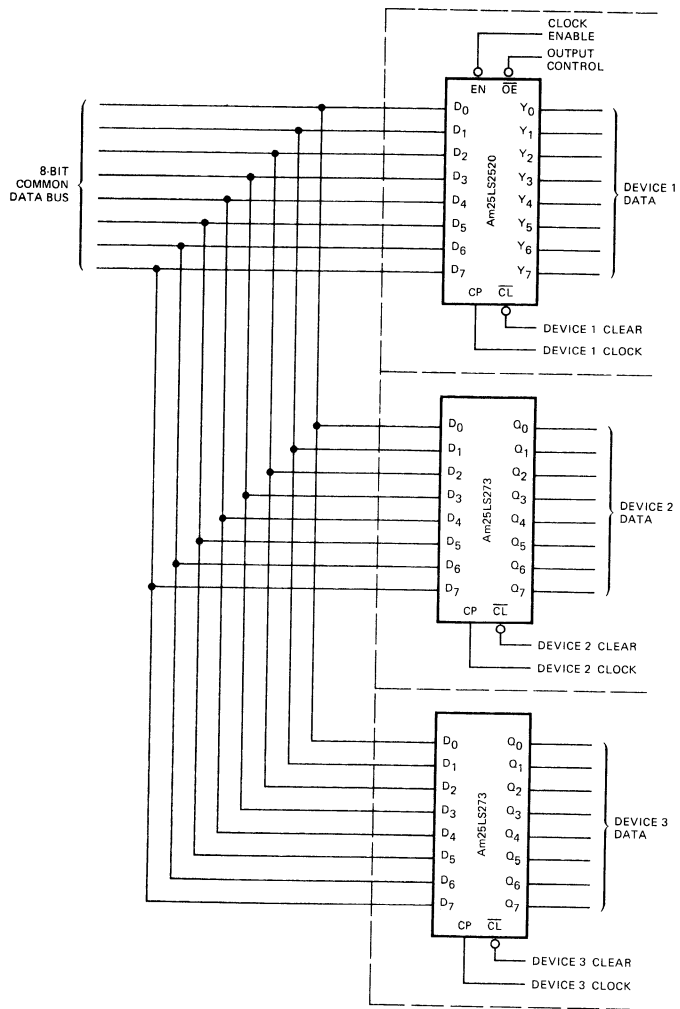


DIE SIZE 0.080" X 0.111"

ORDERING INFORMATION

Package Type	Temperature Range	Am25LS273B Order Number	Am54LS/74LS273B Order Number
Molded DIP	0°C to +70°C	AM25LS273BPC	SN74LS273BN
Hermetic DIP	0°C to +70°C	AM25LS273BDC	SN74LS273BJ
Dice	0°C to +70°C	AM25LS273BXC	SN74LS273BX
Hermetic DIP	-55°C to +125°C	AM25LS273BDM	SN54LS273BJ
Hermetic Flat Pak	-55°C to +125°C	AM25LS273BFM	SN54LS273BW
Dice	-55°C to +125°C	AM25LS273BXM	SN54LS273BX

APPLICATION



Am25LS273 8-bit registers are shown used as device data input registers on a common 8-bit data bus.

Am25LS281 • Am54LS/74LS281

4-Bit Parallel Binary Accumulator

DISTINCTIVE CHARACTERISTICS

- Four-bit binary accumulator
- Fifteen-function ALU
 - 8 arithmetic functions
 - 7 logic functions
- Edge-triggered register
- Full shifting capability
 - Logical shift up
 - Logical shift down
 - Arithmetic shift up
 - Arithmetic shift down
 - Parallel load
 - Hold
- Expandable
 - Ripple expansion with C_n, C_{n+4}
 - Look-ahead carry expansion with \bar{P}, \bar{G}, C_n and Am2902 high-speed look-ahead carry generator
- No dynamic hazard

The Am25LS281 and Am54LS/74LS281 do not have the dynamic hazard found on the A inputs of the SN54S/74S281.

Note: The Advanced Micro Devices: LS281 products were designed prior to publication of data sheets by T.I. Review specifications for possible differences.

FUNCTIONAL DESCRIPTION

The Am25LS281 • Am54LS/74LS281 is a four-bit parallel binary accumulator. As shown in the block diagram, it consists of an ALU, a shift multiplexer, an edge-triggered B register, and the necessary instruction decoding logic.

The ALU performs 15 functions, 8 arithmetic and 7 logical, as defined by Tables 1 and 2. All ALU operations are performed on the A_0 - A_3 inputs and/or the internal B register. The 7 logical functions are performed on an individual bit basis between the A_0 - A_3 inputs and the internal B register. The result of the ALU operation is available at the F_0 - F_3 outputs.

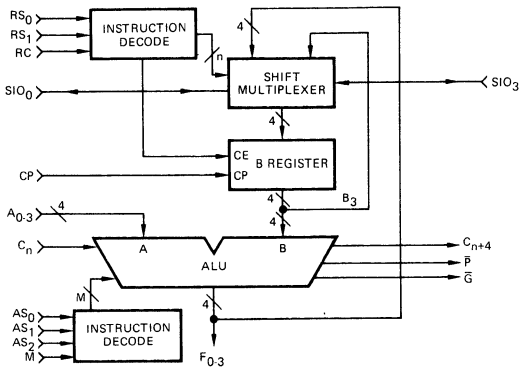
An internal full look-ahead carry scheme is used for high-speed arithmetic operations and provision is made for further look-ahead by including both carry propagate (\bar{P}) and carry generate (\bar{G}) outputs. In slower systems, the carry output C_{n+4} can be connected to the next higher C_n to provide ripple block arithmetic.

The F_0 - F_3 outputs are also used as inputs to the shift multiplexer which either performs one of four shift functions on the data or passes the data unaltered. The outputs of the shift multiplexer are loaded into the internal B register on the LOW to-HIGH transition of the clock input unless both register select inputs (RS_0, RS_1) are high. As shown in Table 3, the shift multiplexer and clock enable for the B register are controlled by the register select (RS_0, RS_1) and register control (RC) inputs. The shift multiplexer is expanded by connecting the SIO_3 input/output to the SIO_0 of the next most significant device.

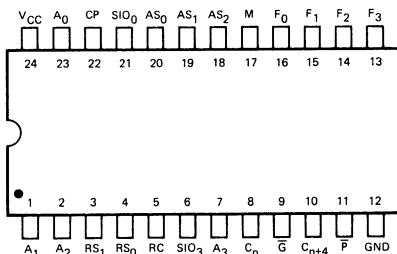
The arithmetic shift functions allow the shifting of a number without effecting the sign bit, the most significant bit of the most significant device. When cascading devices, the RC input of all the devices except the most significant device should be connected to ground. The RC input of the most significant device then determines whether an arithmetic shift or a logical shift is performed on the entire word.

The ALU section of the device has been redesigned to eliminate the dynamic hazard present at the A inputs on the SN54S/74S (T.I.) device. On the AMD device, any time a function is performed using only the B register as an input, the A input is inhibited at the ALU input.

BLOCK DIAGRAM

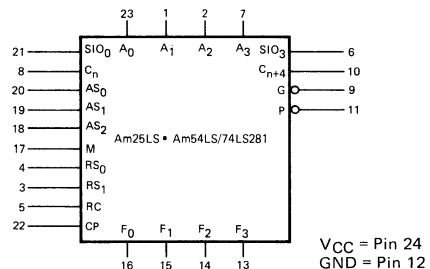


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 24
GND = Pin 12

3

Am25LS/54LS/74LS281

Am25LS281

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)

MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)		Units		
			Min.	Max.			
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A},$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4	Volts	
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.4	Volts	
			$I_{OL} = 8.0\text{mA}$		0.45		
			$I_{OL} = 16\text{mA}$ (\bar{G} only)		0.55		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0		Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	$A_0\text{-}A_3, RS_0, RS_1, RC, SIO_0$		-0.36	mA	
			CP, SIO_3		-0.72		
			$AS_0\text{-}AS_2, M, C_n$		-0.24		
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	$A_0\text{-}A_3, RS_0, RS_1, RC, SIO_0,$ $AS_0\text{-}AS_2, M, C_n$		20	μA	
			CP, SIO_3		40		
I_I	Input HIGH Current	$V_{CC} = \text{MAX.},$	$V_{IN} = 5.5\text{V}$	Clock, SIO_0, SIO_3		1.0	mA
			$V_{IN} = 7.0\text{V}$	Others		1.0	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15	-85	mA	
I_{CC}	Power Supply Current (Note 5)	$V_{CC} = \text{MAX.}$		43	71	mA	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. These are three-state outputs internally connected to TTL inputs. Input characteristics are measured with RS_0, RS_1 in a state such that the three-state output is OFF.
 5. Test Conditions: $AS_0, AS_1, AS_2 = \text{HIGH}$. $RS_0, RS_1, RC, C_n, M, CP, A_0, A_1, A_2, A_3 = \text{GND}$.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to $+V_{CC}$ max.
DC Input Voltage (Clock, SIO_0, SIO_3)	-0.5V to +5.5V
DC Input Voltage (Others)	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am54LS/74LS281

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\%$	(MIN. = 4.75V	MAX. = 5.25V)
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\%$	(MIN. = 4.50V	MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)		Units		
			Min.	Max.			
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}, V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4	Volts	
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}, V_{IN} = V_{IH} \text{ or } V_{IL}$	All, $I_{OL} = 4.0\text{mA}$		0.4	Volts	
			74LS only, $I_{OL} = 8.0\text{mA}$		0.5		
			All, $I_{OL} = 16\text{mA}$ (\bar{G} only)		0.55		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0		Volts		
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	$A_0\text{-}A_3, RS_0, RS_1, RC, SIO_0$		-0.36	mA	
			CP, SIO_3		-0.72		
			$AS_0\text{-}AS_2, M, C_n$		-0.24		
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	$A_0\text{-}A_3, RS_0, RS_1, RC, SIO_0, AS_0\text{-}AS_2, M, C_n$		20	μA	
			CP, SIO_3		40		
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$	$V_{IN} = 5.5\text{V}$	Clock, SIO_0, SIO_3		1.0	mA
			$V_{IN} = 7.0\text{V}$	Others		1.0	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-100	mA	
I_{CC}	Power Supply Current (Note 5)	$V_{CC} = \text{MAX.}$		43	71	mA	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}, 25^\circ\text{C}$, ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. These are three-state outputs internally connected to TTL inputs. Input characteristics are measured with RS_0, RS_1 in a state such that the three-state output is OFF.5. Test Conditions: $AS_0, AS_1, AS_2 = \text{HIGH}$. $RS_0, RS_1, RS, C_n, M, CP, A_0, A_1, A_2, A_3 = \text{GND}$.

DEFINITION OF FUNCTIONAL TERMS

A_0, A_1, A_2, A_3	The A data inputs to the ALU.	\bar{P}	The carry-propagate output for use in multi-level look-ahead schemes.
AS_0, AS_1, AS_2	The control inputs used to determine the arithmetic or logic function performed by the ALU.	RS_0, RS_1, RC	The control inputs used to determine the shift function performed by the shift multiplexer and generate the clock enable signal for the B register.
F_0, F_1, F_2, F_3	The data outputs of the ALU.	SIO_0	The low order serial input/output used to expand the shift multiplexer.
M	The mode control input used to select either the arithmetic or logic operations of the ALU.	SIO_3	The high order serial input/output used to expand the shift multiplexer.
C_n	The carry-in input of the ALU.	CP	The clock input. The internal B register is loaded on the low-to-high transition of the clock input.
C_{n+4}	The carry-look-ahead output of the four-bit field.		
\bar{G}	The carry-generate output for use in multi-level look-ahead schemes.		

Am25LS/54LS/74LS281

SWITCHING CHARACTERISTICS

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	C _n to C _{n+4}		16					ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			15						
t _{PLH}	A ₀ -A ₃ to C _{n+4}		25					ns	
t _{PHL}			23						
t _{PLH}	C _n to F ₀ -F ₃		34					ns	
t _{PHL}			28						
t _{PLH}	A ₀ -A ₃ to \bar{G}		18					ns	
t _{PHL}			17						
t _{PLH}	A ₀ -A ₃ to \bar{F}		21					ns	
t _{PHL}			23						
t _{PLH}	A _n to F _n		29					ns	
t _{PHL}			23						
t _{PLH}	A ₀ to SIO ₀		38					ns	
t _{PHL}			36						
t _{PLH}	A ₂ , A ₃ to SIO ₃		39					ns	
t _{PHL}			36						
t _{PLH}	F ₀ to SIO ₀							ns	
t _{PHL}									
t _{PLH}	F ₂ , F ₃ to SIO ₃							ns	
t _{PHL}									
t _{PLH}	RC to SIO ₃							ns	
t _{PHL}									
t _{PLH}	AS ₀ -AS ₂ , M to F ₀ -F ₃		40					ns	
t _{PHL}			33						
t _{PLH}	AS ₀ -AS ₂ , M to C _{n+4}		41					ns	
t _{PHL}			40						
t _s	A ₀ -A ₃ to CP							ns	
t _h									
t _s	C _n to CP							ns	
t _h									
t _s	AS ₀ -AS ₂ , M to CP							ns	
t _h									
t _s	SIO ₀ to CP							ns	
t _h									
t _s	SIO ₃ to CP							ns	
t _h									
t _s	RS ₀ , RS ₁ , RC to CP							ns	
t _h									
t _{pw}	CP Pulse Width	HIGH						ns	
		LOW							
f _{max} (Note 1)	Clock Frequency (Shift Mode)							MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

SWITCHING CHARACTERISTICS

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{ZH}	RS ₀ , RS ₁ to SIO ₀		9					ns	C _L = 15pF R _L = 2.0kΩ
t _{ZL}			8						
t _{HZ}			29						
t _{LZ}	RS ₀ , RS ₁ to SIO ₃		18					ns	C _L = 5.0pF R _L = 2.0kΩ
t _{ZH}			9						
t _{ZL}			8						
t _{HZ}	AS ₀ -AS ₂ , M to \bar{P}		32					ns	C _L = 15pF R _L = 2.0kΩ
t _{PLH}			30						
t _{PHL}			33						
t _{PLH}	AS ₀ -AS ₂ , M to \bar{G}		32					ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			32						
t _{PHL}									
t _{PLH}	CP to F ₀ -F ₃							ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}									
t _{PLH}	CP to C _{n+4}							ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}									
t _{PLH}	CP to \bar{P}							ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}									
t _{PLH}	CP to \bar{G}							ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}									
t _{PLH}	CP to SIO ₀							ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}									
t _{PLH}	CP to SIO ₃							ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}									

3

FUNCTION TABLES

TABLE 1
ARITHMETIC FUNCTIONS
Mode Control (M) = Low

ALU SELECTION			ACTIVE-HIGH DATA	
AS ₂	AS ₁	AS ₀	C _n = H (with carry)	C _n = L (no carry)
L	L	L	F ₀ = L, F ₁ = F ₂ = F ₃ = H	F _n = H
L	L	H	F = B Minus A	F = B Minus A Minus 1
L	H	L	F = A Minus B	F = A Minus B Minus 1
L	H	H	F = A Plus B Plus 1	F = A Plus B
H	L	L	F = B Plus 1	F _n = B _n
H	L	H	F = \bar{B} Plus 1	F _n = \bar{B}_n
H	H	L	F = A Plus 1	F _n = A _n
H	H	H	F = \bar{A} Plus 1	F _n = \bar{A}_n

TABLE 2
LOGIC FUNCTIONS
Mode Control (M) = High
Carry Input (C_n) = X (Irrelevant)

ALU SELECTION			ACTIVE-HIGH DATA FUNCTION
AS ₂	AS ₁	AS ₀	
L	L	L	F _n = L
L	X	H	F _n = A _n ⊕ B _n
L	H	L	F _n = A _n ⊕ B _n
H	L	L	F _n = A _n B _n
H	L	H	F _n = A _n + B _n
H	H	L	F _n = A _n B _n
H	H	H	F _n = A _n + B _n

TABLE 3
SHIFT MODE FUNCTIONS

REG. SEL. INPUTS			OPERATION	B REGISTER AFTER L → H CLOCK TRANSITION				SERIAL INPUTS/OUTPUTS	
RS ₁	RS ₀	RC		Q _{B0}	Q _{B1}	Q _{B2}	Q _{B3}	SIO ₀	SIO ₃
L	L	X	Load B Reg. (F → B)	f ₀	f ₁	f ₂	f ₃	Z	Z
L	H	L	Shift Up (2F → B)	SIO ₀	f ₀	f ₁	f ₂	Z	F ₃
L	H	H	Arith. Shift Up	SIO ₀	f ₀	f ₁	B ₃	Z	F ₂
H	L	L	Shift Down (F/2 → B)	f ₁	f ₂	f ₃	SIO ₃	F ₀	Z
H	L	H	Arith. Shift Down	f ₁	f ₂	SIO ₃	B ₃	F ₀	Z
H	H	X	Hold	B ₀	B ₁	B ₂	B ₃	Z	Z

Q_{Bn} = Output of the B register (internal).f_n = Quiescent state of F_n output prior to L → H CP transition.B_n = Quiescent state of Q_{Bn} output prior to L → H CP transition.

Z = High impedance state (output OFF).

Am25LS/54LS/74LS281

Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	C _n to C _{N+4}					ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}							
t _{PLH}	A ₀ -A ₃ to C _{n+4}					ns	
t _{PHL}							
t _{PLH}	C _n to F ₀ -F ₃					ns	
t _{PHL}							
t _{PLH}	A ₀ -A ₃ to \bar{G}					ns	
t _{PHL}							
t _{PLH}	A ₀ -A ₃ to \bar{P}					ns	
t _{PHL}							
t _{PLH}	A _n to F _n					ns	
t _{PHL}							
t _{PLH}	A ₀ to SIO ₀					ns	
t _{PHL}							
t _{PLH}	A ₂ , A ₃ to SIO ₃					ns	
t _{PHL}							
t _{PLH}	F ₀ to SIO ₀					ns	
t _{PHL}							
t _{PLH}	F ₂ , F ₃ to SIO ₃					ns	
t _{PHL}							
t _{PLH}	RC to SIO ₃					ns	
t _{PHL}							
t _{PLH}	AS ₀ -AS ₂ , M to F ₀ -F ₃					ns	
t _{PHL}							
t _{PLH}	AS ₀ -AS ₂ , M to C _{n+4}					ns	
t _{PHL}							
t _s	A ₀ -A ₃ to CP					ns	
t _h							
t _s	C _n to CP					ns	
t _h							
t _s	AS ₀ -AS ₂ , M to CP					ns	
t _h							
t _s	SIO ₀ to CP					ns	
t _h							
t _s	SIO ₃ to CP					ns	
t _h							
t _s	RS ₀ , RS ₁ , RC to CP					ns	
t _h							
t _{pw}	CP Pulse Width					ns	
		HIGH					
		LOW					
f _{Max.}	Clock Frequency (Shift Mode)					MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{ZH}	RS ₀ , RS ₁ to SIO ₀					ns	C _L = 15pF R _L = 2.0kΩ
t_{ZL}							
t_{HZ}						ns	
t_{LZ}							
t_{ZH}	RS ₀ , RS ₁ to SIO ₃					ns	C _L = 15pF R _L = 2.0kΩ
t_{ZL}							
t_{HZ}						ns	
t_{LZ}							
t_{PLH}	AS ₀ -AS ₂ , M to \bar{P}					ns	C _L = 50pF R _L = 2.0kΩ
t_{PHL}							
t_{PLH}	AS ₀ -AS ₂ , M to \bar{G}					ns	
t_{PHL}							
t_{PLH}	CP to F ₀ -F ₃					ns	
t_{PHL}							
t_{PLH}	CP to C _{n+4}					ns	
t_{PHL}							
t_{PLH}	CP to \bar{P}					ns	
t_{PHL}							
t_{PLH}	CP to \bar{G}					ns	
t_{PHL}							
t_{PLH}	CP to SIO ₀					ns	
t_{PHL}							
t_{PLH}	CP to SIO ₃					ns	
t_{PHL}							

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

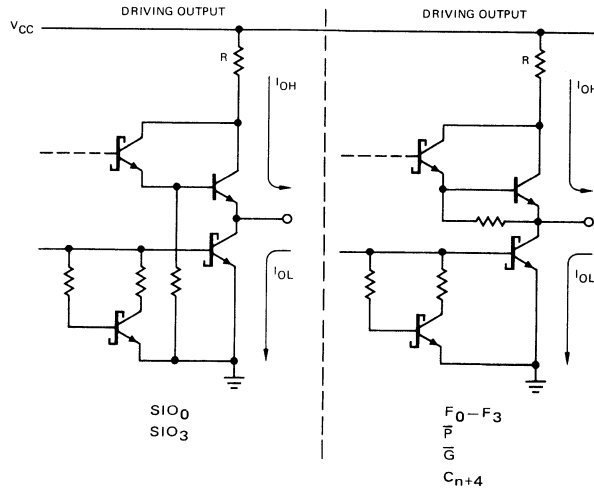
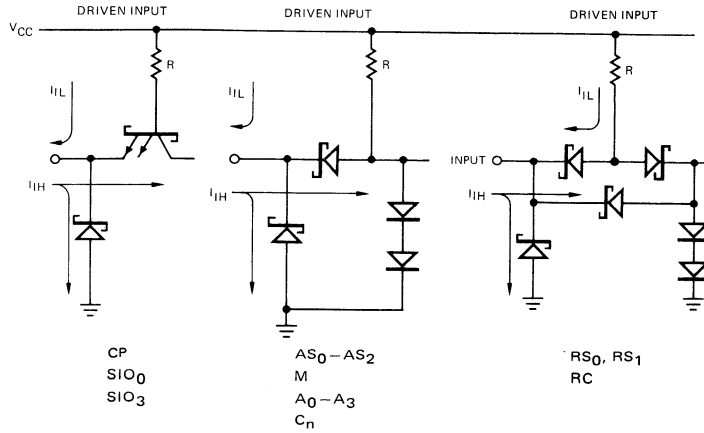
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TABLE 4. \bar{G} , \bar{P} AND CARRY FUNCTIONS FOR OUTPUTS

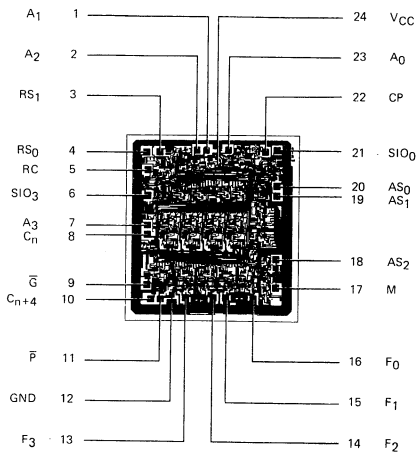
INPUTS				DEFINITION OF TERMS		OUTPUTS		
M	AS ₂	AS ₁	AS ₀	P _n	G _n	\bar{P}	\bar{G}	C _{n+4}
L	L	L	L	N.A.	N.A.	L	H	C _n
L	L	L	H	$\bar{A}_n + B_n$	$\bar{A}_n \cdot B_n$	$\bar{P}_3 P_2 P_1 P_0$	$\bar{G}_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0$	G + P · C _n
L	L	H	L	$A_n + \bar{B}_n$	$A_n \cdot \bar{B}$	$\bar{P}_3 P_2 P_1 P_0$	$\bar{G}_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0$	G + P · C _n
L	L	H	H	$A_n + B_n$	$A_n \cdot B_n$	$\bar{P}_3 P_2 P_1 P_0$	$\bar{G}_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0$	G + P · C _n
L	H	L	L	B _n	N.A.	$\bar{P}_3 P_2 P_1 P_0$	H	P · C _n
L	H	L	H	\bar{B}_n	N.A.	$\bar{P}_3 P_2 P_1 P_0$	H	P · C _n
L	H	H	L	A _n	N.A.	$\bar{P}_3 P_2 P_1 P_0$	H	P · C _n
L	H	H	H	\bar{A}_n	N.A.	$\bar{P}_3 P_2 P_1 P_0$	H	P · C _n
H	L	L	L	N.A.	N.A.	L	H	C _n
H	L	L	H	$\bar{A}_n + B_n$	$\bar{A}_n \cdot B_n$	$\bar{P}_3 P_2 P_1 P_0$	$\bar{G}_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0$	G + P · C _n
H	L	H	L	$A_n + B_n$	$A_n \cdot B_n$	$\bar{P}_3 P_2 P_1 P_0$	$\bar{G}_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0$	G + P · C _n
H	L	H	H	$\bar{A}_n + B_n$	$\bar{A}_n \cdot B_n$	$\bar{P}_3 P_2 P_1 P_0$	$\bar{G}_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0$	G + P · C _n
H	H	L	L	N.A.	$A_n \cdot B_n$	L	$\bar{G}_3 + G_2 + G_1 + G_0$	G + C _n
H	H	L	H	N.A.	$\bar{A}_n \cdot \bar{B}_n$	L	$\bar{G}_3 + G_2 + G_1 + G_0$	G + C _n
H	H	H	L	N.A.	$A_n \cdot B_n$	L	$\bar{G}_3 + G_2 + G_1 + G_0$	G + C _n
H	H	H	H	N.A.	$\bar{A}_n \cdot \bar{B}_n$	L	$\bar{G}_3 + G_2 + G_1 + G_0$	G + C _n

N.A. = Not Applicable.

**INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**



Metallization and Pad Layout

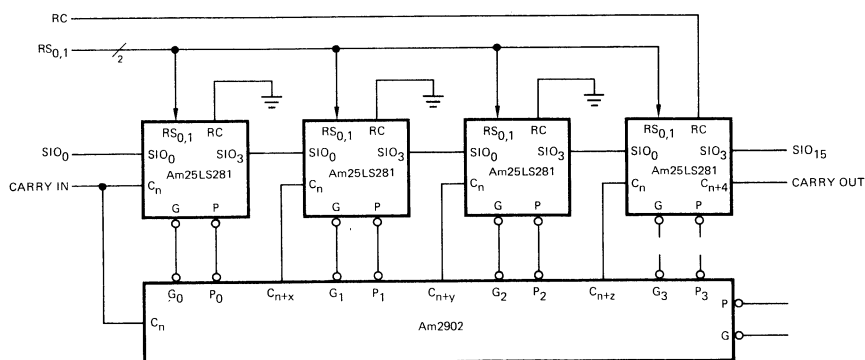


DIE SIZE 0.111" X 0.121"

ORDERING INFORMATION

Package Type	Temperature Range	Am25LS281 Order Number	Am54LS/74LS281 Order Number
Molded DIP	0°C to +70°C	AM25LS281PC	SN74LS281N
Hermetic DIP	0°C to +70°C	AM25LS281DC	SN74LS281J
Dice	0°C to +70°C	AM25LS281XC	SN74LS281X
Hermetic DIP	-55°C to +125°C	AM25LS281DM	SN54LS281J
Hermetic Flat Pak	-55°C to +125°C	AM25LS281FM	SN54LS281W
Dice	-55°C to +125°C	AM25LS281XM	SN54LS281X

APPLICATION



16-Bit Binary ALU/Accumulator with Full Look-Ahead Carry.

TABLE 4. \bar{G} , \bar{P} AND CARRY FUNCTIONS FOR OUTPUTS

INPUTS				DEFINITION OF TERMS			OUTPUTS	
M	AS ₂	AS ₁	AS ₀	P _n	G _n	\bar{P}	\bar{G}	C _{n+4}
L	L	L	L	N.A.	N.A.	L	H	C _n
L	L	L	H	$\bar{A}_n + B_n$	$\bar{A}_n \cdot B_n$	$\overline{P_3 P_2 P_1 P_0}$	$\overline{G_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0}$	G + P · C _n
L	L	H	L	$A_n + \bar{B}_n$	$A_n \cdot \bar{B}$	$\overline{P_3 P_2 P_1 P_0}$	$\overline{G_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0}$	G + P · C _n
L	L	H	H	$A_n + B_n$	$A_n \cdot B_n$	$\overline{P_3 P_2 P_1 P_0}$	$\overline{G_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0}$	G + P · C _n
L	H	L	L	B _n	N.A.	$\overline{P_3 P_2 P_1 P_0}$	H	P · C _n
L	H	L	H	\bar{B}_n	N.A.	$\overline{P_3 P_2 P_1 P_0}$	H	P · C _n
L	H	H	L	A _n	N.A.	$\overline{P_3 P_2 P_1 P_0}$	H	P · C _n
L	H	H	H	\bar{A}_n	N.A.	$\overline{P_3 P_2 P_1 P_0}$	H	P · C _n
H	L	L	L	N.A.	N.A.	L	H	C _n
H	L	L	H	$\bar{A}_n + B_n$	$\bar{A}_n \cdot B_n$	$\overline{P_3 P_2 P_1 P_0}$	$\overline{G_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0}$	G + P · C _n
H	L	H	L	$A_n + B_n$	$A_n \cdot B_n$	$\overline{P_3 P_2 P_1 P_0}$	$\overline{G_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0}$	G + P · C _n
H	L	H	H	$\bar{A}_n + B_n$	$\bar{A}_n \cdot B_n$	$\overline{P_3 P_2 P_1 P_0}$	$\overline{G_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0}$	G + P · C _n
H	H	L	L	N.A.	$A_n \cdot B_n$	L	$G_3 + G_2 + G_1 + G_0$	G + C _n
H	H	L	H	N.A.	$\bar{A}_n \cdot \bar{B}_n$	L	$G_3 + G_2 + G_1 + G_0$	G + C _n
H	H	H	L	N.A.	$A_n \cdot B_n$	L	$G_3 + G_2 + G_1 + G_0$	G + C _n
H	H	H	H	N.A.	$\bar{A}_n \cdot \bar{B}_n$	L	$G_3 + G_2 + G_1 + G_0$	G + C _n

N.A. = Not Applicable.

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Am25LS299 • Am54LS/74LS299

8-Bit Universal Shift/Storage Register

DISTINCTIVE CHARACTERISTICS

- Four operational modes: shift left, shift right, parallel load, hold
- Common input/output pins
- Three-state outputs
- Buffered asynchronous master clear
- Separate shift right serial input and shift left serial input for easy cascadability
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL} at $I_{OL} = 8\text{mA}$
 - Twice the fan-out over military range
 - 440 μA source current at HIGH output
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

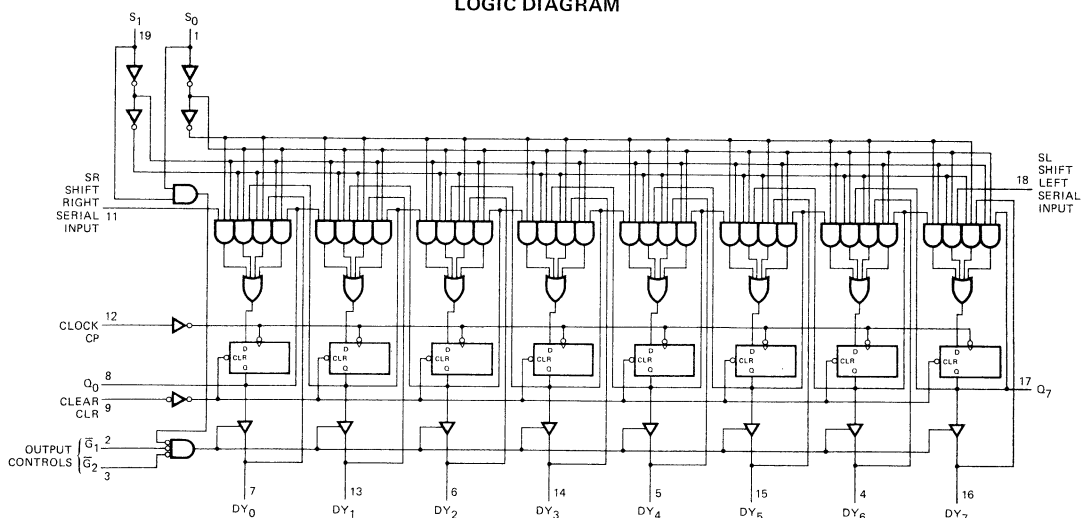
The Am25LS299 and Am54LS/74LS299 are eight-bit universal shift/storage registers with three-state outputs. Four modes of operation are possible: hold (store), shift left, shift right, and load data.

Parallel load inputs and register outputs are multiplexed to reduce the total number of package pins. Separate continuous outputs are also provided for flip-flop A and H. These devices can be cascaded to N-bit words easily.

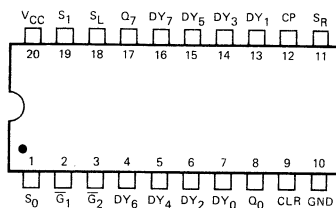
A separate active low asynchronous clear input is used to reset the register. Whenever the clear input is LOW, all internal flip-flops are set LOW independent of all other inputs. See the Am25LS23 for the identical logic function to the Am25LS299 and Am54LS/74LS299, but with synchronous clear capability.

Note: The Advanced Micro Devices' LS299 products were designed prior to publication of data sheets by T.I. Review specifications for possible differences.

LOGIC DIAGRAM

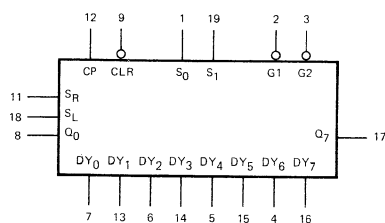


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



$V_{CC} = \text{Pin } 20$
 $GND = \text{Pin } 10$

Am25LS299

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25V
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	Q_0, Q_7	$I_{OH} =$ $-440\mu\text{A}$	MIL	2.5		Volts
					COM'L	2.7		
		DY ₀ -DY ₇	MIL, $I_{OH} = -1.0\text{mA}$		2.4			
			COM'L, $I_{OH} = -2.6\text{mA}$		2.4			
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}		$I_{OL} = 4.0\text{mA}$		0.25	0.4	Volts
				$I_{OL} = 8.0\text{mA}$		0.35	0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs			2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			MIL		0.7	Volts
					COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$					-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$		S_0, S_1		-0.8	mA	
				All Others		-0.4		
I_{IH}	Input HIGH Current (Except DY _i)	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$		S_0, S_1		40	μA	
				All Others		20		
I_I	Input HIGH Current (Except DY _i)	$V_{CC} = \text{MAX.},$	$V_{IN} = 7.0\text{V}$	S_0, S_1		0.2	μA	
				$\bar{G}_1, \bar{G}_2, \text{CLR}, \text{CP}$		0.1		
				All Others		0.1		
I_{OZ}	Off-State (High-Impedance) Output Current at DY _i	$V_{CC} = \text{MAX.}$		$V_O = 0.4\text{V}$		-100	μA	
				$V_O = 2.4\text{V}$		40		
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$			-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$				38	60	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CC} measured with clock input HIGH and output controls HIGH.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to + V_{CC} max.
DC Input Voltage ($\bar{G}_1, \bar{G}_2, \text{CLR}, \text{CP}, S_0, S_1$)	-0.5V to +7.0V
DC Input Voltage (Others)	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25V
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

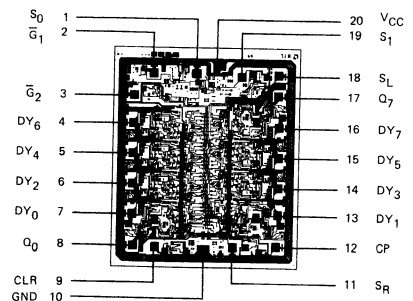
Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)		Units	
			Min.	Max.		
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	Q_0, Q_7	MIL	2.5	Volts
				COM'L	2.7	
		DY_0-DY_7	MIL, $I_{OH} = -1.0\text{mA}$	2.4		
			COM'L, $I_{OH} = -2.6\text{mA}$	2.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4.0\text{mA}$	0.25	0.4	Volts
			$I_{OL} = 8.0\text{mA}$ 74LS only	0.35	0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0		Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$	S_0, S_1		-0.8	mA
			All Others		-0.4	
I_{IH}	Input HIGH Current (Except DY_i)	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$	S_0, S_1		40	μA
			All Others		20	
I_I	Input HIGH Current (Except DY_i)	$V_{CC} = \text{MAX.}$, $V_{IN} = 5.5\text{V}$	S_0, S_1		0.2	mA
			All Others		0.1	
I_{OZ}	Off-State (High-Impedance) Output Current at DY_i	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$		-100	μA
			$V_O = 2.4\text{V}$		40	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-100	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		35	60	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CC} measured with clock input HIGH and output controls HIGH.

DEFINITION OF FUNCTIONAL TERMS

- SR** Shift right data input to Q_0
SL Shift left data input to Q_7
Clear Active LOW synchronous input forcing the Q_0 through Q_7 register to see LOW conditions, visible only if outputs are enabled
Clock A LOW-to-HIGH transition will result in the register changing state to next state as described by mode and input data condition
 S_0, S_1 Mode selection control lines used to control input (output during load) conditions
 \bar{G}_1, \bar{G}_2 Active LOW input to control three-state output in active LOW AND configuration
 Q_0, Q_7 The only two direct outputs; used to cascade shift operations
 DY_0-DY_7 Input/Output line dependent on mode and output control. Input only with mode select LOAD. Output in all other modes but subject to output select (G_1, G_2).

Metallization and Pad Layout



DIE SIZE 0.096" X 0.112"

SWITCHING CHARACTERISTICS(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	Clock to Q _i		18	26			30	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			22	28			34		
t _{PLH}	Clock to DY _i		18	26			30	ns	
t _{PHL}			22	28			34		
t _{PHL}	Clear to DY ₀ - DY ₇		25	35			35	ns	
t _{PHL}	Clear to Q ₀ or Q ₇		25	35			35	ns	
t _{pw}	Pulse Width (Clock)	15			20			ns	
t _s	S ₁ , S ₀ Set-up Time	12			15			ns	
t _s	DY _i or S _R , S _L Data Set-up Time	12			15			ns	
t _h	Hold Time	3.0			3.0			ns	
t _{ZH}	S ₁ , S ₀ , $\overline{G_1}$, $\overline{G_2}$ to DY _i		20	30			40	ns	
t _{ZL}				20	30				40
t _{LZ}	S ₁ , S ₀ , $\overline{G_1}$, $\overline{G_2}$ to DY _i		22	33			40	ns	C _L = 5.0pF R _L = 2.0kΩ
t _{HZ}				15	23				
f _{max}	Maximum Clock Frequency (Note 1)	30	45		25			MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	Clock to Q _i		38		44	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			41		47		
t _{PLH}	Clock to DY _i		38		44	ns	
t _{PHL}			41		47		
t _{PHL}	Clear to DY ₀ - DY ₇		50		57	ns	
t _{PHL}	Clear to Q ₀ - Q ₇		50		57	ns	
t _{pw}	Pulse Width (Clock)	24		27		ns	
t _s	S ₁ , S ₀ Set-up Time	20		23		ns	
t _s	DY _i or S _R , S _L Data Set-up Time	20		23		ns	
t _h	Hold Time	8		9		ns	
t _{ZH}	S ₁ , S ₀ , $\overline{G_1}$, $\overline{G_2}$ to DY _i		43		50	ns	
t _{ZL}				43			50
t _{LZ}	S ₁ , S ₀ , $\overline{G_1}$, $\overline{G_2}$ to DY _i		43		50	ns	C _L = 5.0pF R _L = 2.0kΩ
t _{HZ}				34			
f _{max}	Maximum Clock Frequency (Note 1)	23		20		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

3

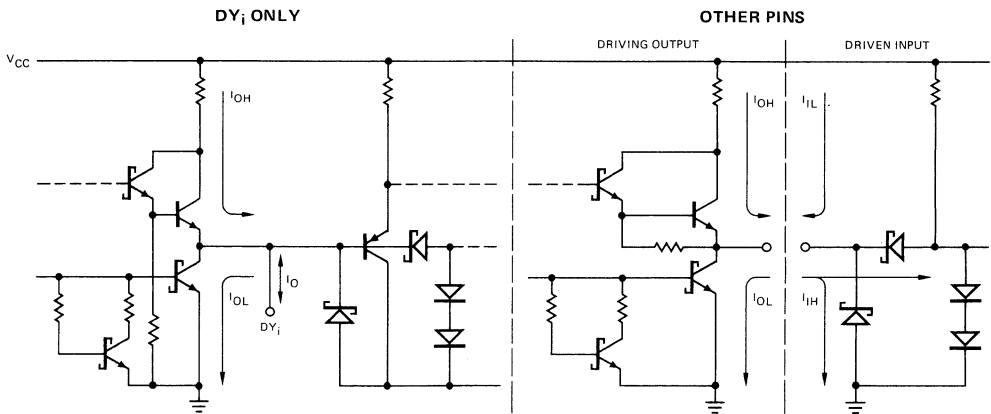
TRUTH TABLE

FUNCTION		INPUTS						OUTPUTS		INPUTS/OUTPUTS									
		S _R	S _L	CLEAR	CLOCK	S ₀	S ₁	\overline{G}_1	\overline{G}_2	Q ₀	Q ₇	DY ₀	DY ₁	DY ₂	DY ₃	DY ₄	DY ₅	DY ₆	DY ₇
Clear		X	X	L	X	(Note 1)	L	L	L	L	L	L	L	L	L	L	L	L	L
Output Control		X	X	X	X	X	X	H	L	NC	NC	Z	Z	Z	Z	Z	Z	Z	Z
		X	X	X	X	X	X	L	H	NC	NC	Z	Z	Z	Z	Z	Z	Z	Z
		X	X	X	X	X	X	H	H	NC	NC	Z	Z	Z	Z	Z	Z	Z	Z
M	Hold	X	X	H	X	L	L	L	L	NC	NC	NC	NC	NC	NC	NC	NC	NC	NC
	Load (Note 2)	X	X	H	↑	H	H	L	L	A	H	A-	B	C	D	E	F	G	H
O	Shift Right	L	X	H	↑	H	L	L	L	L	DY ₆	L	DY ₀	DY ₁	DY ₂	DY ₃	DY ₄	DY ₅	DY ₆
D	Shift Right	H	X	H	↑	H	L	L	L	H	DY ₆	H	DY ₀	DY ₁	DY ₂	DY ₃	DY ₄	DY ₅	DY ₆
E	Shift Left	X	L	H	↑	L	H	L	L	DY ₁	L	DY ₁	DY ₂	DY ₃	DY ₄	DY ₅	DY ₆	DY ₇	L
	Shift Left	X	H	H	↑	L	H	L	L	DY ₁	H	DY ₁	DY ₂	DY ₃	DY ₄	DY ₅	DY ₆	DY ₇	H

L = LOW Z = High Impedance ↑ = Transition LOW-to-HIGH
 H = HIGH X = Don't Care NC = No Change

Notes: 1. Either LOW to observe outputs.
 2. In this mode DY_i are inputs.

Am25LS • Am54LS/74LS
 LOW-POWER SCHOTTKY INPUT/OUTPUT
 CURRENT INTERFACE CONDITIONS

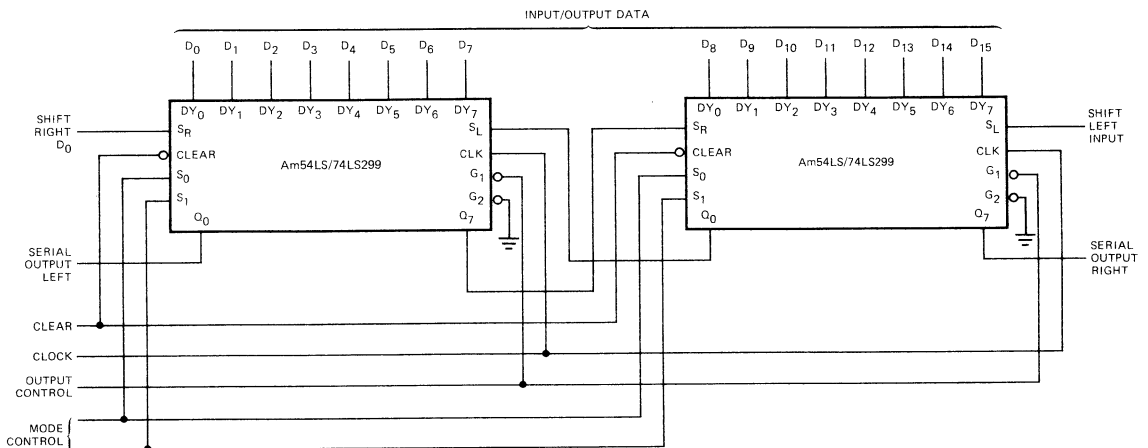


Note: Actual current flow direction shown.

ORDERING INFORMATION

Package Type	Temperature Range	Am25LS299 Order Number	Am54LS/74LS299 Order Number
Molded DIP	0°C to +75°C	AM25LS299PC	SN74LS299N
Hermetic DIP	0°C to +75°C	AM25LS299DC	SN74LS299J
Dice	0°C to +75°C	AM25LS299XC	SN74LS299X
Hermetic DIP	-55°C to +125°C	AM25LS299DM	SN54LS299J
Hermetic Flat Pak	-55°C to +125°C	AM25LS299FM	SN54LS299W
Dice	-55°C to +125°C	AM25LS299XM	SN54LS299X

APPLICATION



16-Bit Cascaded Parallel Load/Unload Shift Right/Left Register.

Am25LS322 • Am54LS/74LS322

8-Bit Serial/Parallel Register with Sign Extend

The 'LS322 is Texas Instruments' planned second source to Advanced Micro Devices' Am25LS22.

See Am25LS22 data sheet for full information.

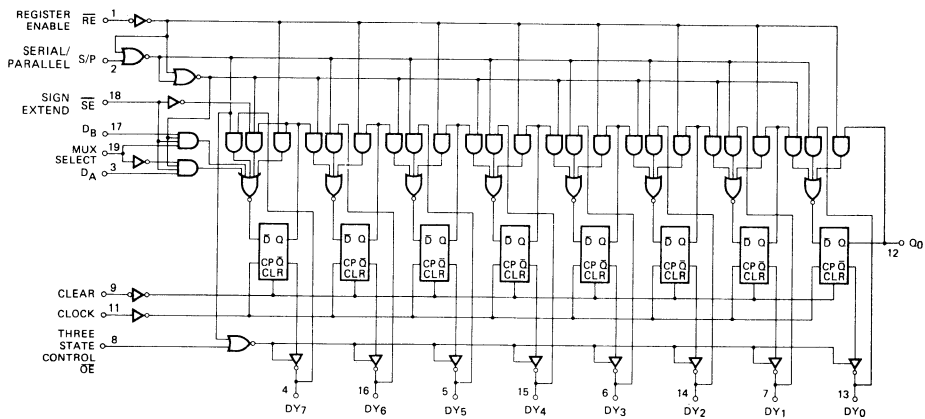
FUNCTIONAL DESCRIPTION

The Am25LS22 is an eight-bit serial/parallel register built using advanced Low-Power Schottky processing. The device features an eight-bit parallel multiplexed input/output port to provide improved bit density in a 20-pin package. Data may also be loaded into the device in a serial manner from either input D_A or D_B . A serial output, Q_0 , is also provided.

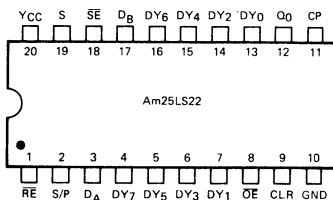
The Am25LS22 is specifically designed for operation with the Am25LS14 serial/parallel two's complement multiplier and provides the sign extend function required for this device.

When the Register Enable (\overline{RE}) input is HIGH, the register will retain its current contents. Synchronous parallel loading is accomplished by applying a LOW to \overline{RE} and applying a LOW to the Serial/Parallel (S/P) input. This places the three-state outputs in the high-impedance state independent of \overline{OE} and allows data that is applied on the input/output lines (DY_i) to be clocked into the register. When the S/P input is HIGH, the device will shift right. The Sign Extend (\overline{SE}) input is used to repeat the sign in the Q_7 flip-flop. This occurs whenever \overline{SE} is LOW when the SHIFT mode is selected. When \overline{SE} is high, the serial two-input multiplexer is enabled. Thus, either D_A or D_B can be selected to load data serially. The register changes state on the LOW-to-HIGH transition of the clock. A clear input (CLR) is used to asynchronously reset all flip-flops when a LOW is applied.

LOGIC DIAGRAM

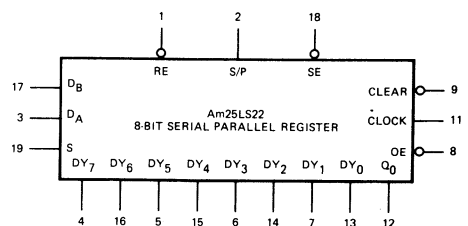


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 20
GND = Pin 10

Am25LS323 • Am54LS/74LS323

8-Bit Shift/Storage Register with Synchronous Clear

The 'LS323 is Texas Instruments' planned second source to Advanced Micro Devices' Am25LS23.

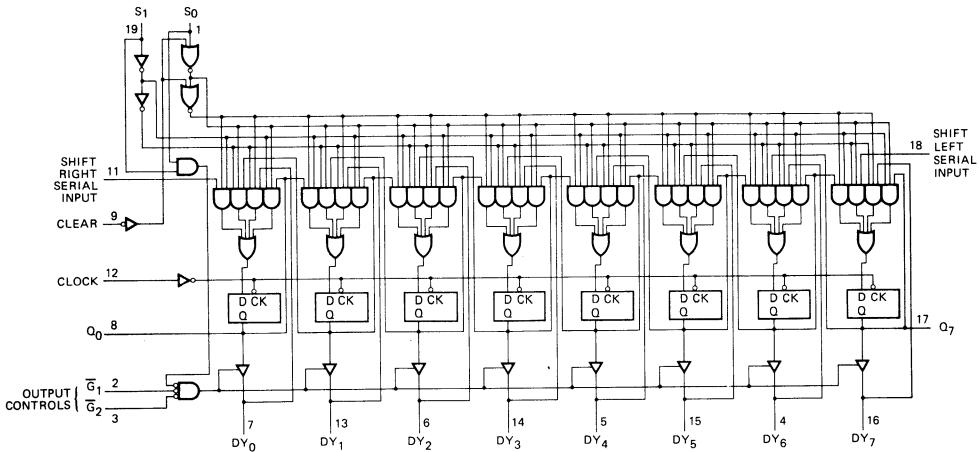
See Am25LS23 data sheet for full information.

FUNCTIONAL DESCRIPTION

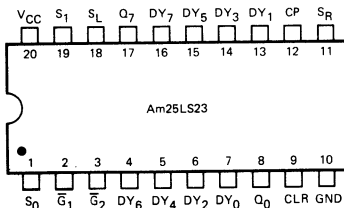
The Am25LS23 is an 8-bit universal shift/storage register with 3-state outputs. The function is similar to the Am25LS299 with the exception of a synchronous clear function. Parallel load inputs and register outputs are multiplexed to allow the use of a 20-pin package. Separate continuous outputs are also provided for flip-flops Q₀ and Q₇.

Four modes of operation are possible — Hold (store), Shift-left, Shift-right and Load Data. The Am25LS23 has a typical shift frequency of 50MHz. The Am25LS23 is packaged in a standard 20-pin package.

LOGIC DIAGRAM

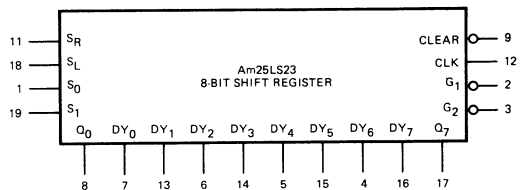


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 20
GND = Pin 10

Am54LS/74LS348

Three-State Priority Encoder

Advanced Micro Devices has no current plans to manufacture this product.

See the Am25LS2513 for a recommended alternative Three-State Priority Encoder offering greater functional flexibility.

Am25LS373 • Am54LS/74LS373

Octal Latches with Three-State Output

DISTINCTIVE CHARACTERISTICS

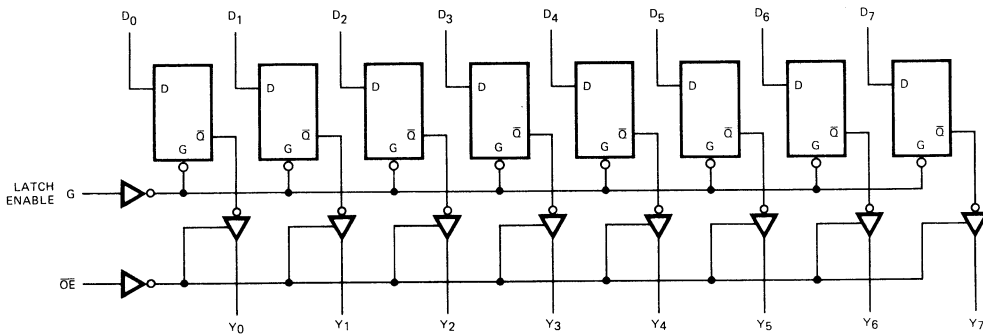
- 8 latches in a single package
- Three-state outputs interface directly with bus organized systems
- Hysteresis on latch enable input for improved noise margin
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - Twice the fan-out over military range
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am25LS373 and Am54LS/74LS373 are octal latches with three-state outputs for bus organized system applications. The latches appear to be transparent to the data (data changes asynchronously) when latch enable, G, is HIGH. When G is LOW, the data that meets the set-up times is latched. Data appears on the bus when the output enable, \overline{OE} , is LOW. When \overline{OE} is HIGH the bus output is in the high-impedance state.

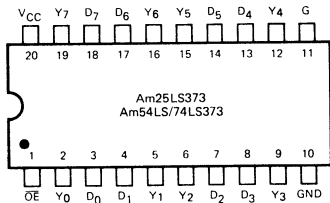
Note: An inverting version of this device, to be called Am54LS/74LS533, is also in development.

LOGIC DIAGRAM Am25LS/54LS/74LS373



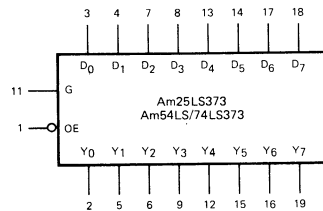
Outputs Y_0 through Y_7 are inverted on the Am25LS/54LS/74LS533.

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 20
 GND = Pin 10

3

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25V
 MIL $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -1.0\text{mA}$	MIL	2.4	3.4	Volts
			$I_{OH} = -2.6\text{mA}$	COM'L	2.4	3.4	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 12\text{mA}$			0.4	Volts
			$I_{OL} = 24\text{mA}$			0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		MIL		0.7	Volts
				COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$				-0.4	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$				20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$				0.1	mA
I_{OZ}	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$			-20	μA
			$V_O = 2.4\text{V}$			20	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$			24	40	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Inputs grounded; outputs open.

Am25LS • Am54LS/74LS**MAXIMUM RATINGS** (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to $+V_{CC}$ max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am54LS/74LS373

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 V
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = MIN. V _{IN} = V _{IH} or V _{IL}	I _{OH} = -1.0 mA MIL	2.4	3.4	Volts	
			I _{OH} = -2.6mA COM'L	2.4	3.4		
V _{OL}	Output LOW Voltage	V _{CC} = MIN. V _{IN} = V _{IH} or V _{IL}	All, I _{OL} = 12mA		0.25	0.4	Volts
			74LS only, I _{OL} = 24mA		0.35	0.5	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0		Volts	
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.5	Volts	
I _{IL}	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.4 V			-0.4	mA	
I _{IH}	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7 V			20	μA	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 7.0 V			0.1	mA	
I _O	Off-State (High-Impedance) Output Current	V _{CC} = MAX.	V _O = 0.4 V		-20	μA	
			V _O = 2.4 V		20		
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.		-15	-100	mA	
I _{CC}	Power Supply Current (Note 4)	V _{CC} = MAX.			24	40	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0 V, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Inputs grounded; outputs open.

3

FUNCTION TABLE

Inputs			Internal	Outputs	Function
OE	G	D _i	Q _i	Y _i	
H	X	X	X	Z	Hi-Z
L	H	L	H	L	
L	H	H	L	H	Transparent
L	L	X	NC	NC	
					Latched

H = HIGH
 L = LOW
 X = Don't Care

NC = No Change
 Z = High Impedance

DEFINITION OF FUNCTIONAL TERMS

- D_i** The latch data inputs.
G The latch enable input. Data is latched upon and set-up and hold times are referenced to the HIGH-to-LOW transition of G.
Y_i The three-state latch outputs.
OE The output enable control. When OE is LOW, the outputs Y_i are enabled. When OE is HIGH, the outputs Y_i are in the high impedance (off) state.

Am25LS/54LS/74LS373

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

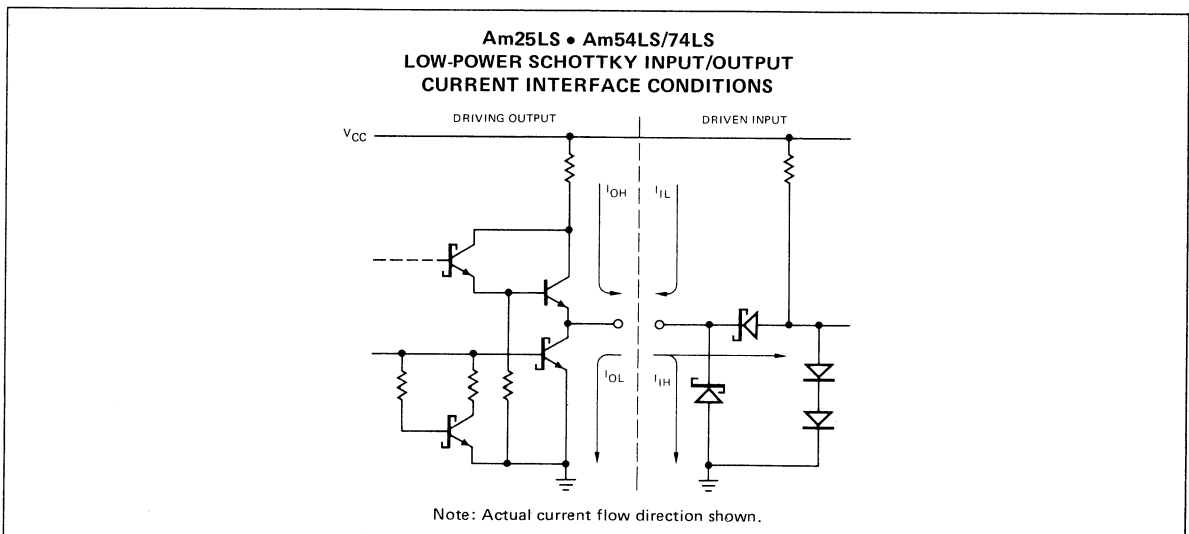
Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Enable to Output					20	30	ns	$C_L = 45\text{pF}$ $R_L = 667\Omega$
t_{PHL}						18	30		
t_{PLH}	Data Input to Output					12	18	ns	
t_{PHL}						12	18		
$t_s(H)$	HIGH Data to Enable				0			ns	
$t_s(L)$	LOW Data to Enable				0				
$t_h(H)$	HIGH Data to Enable				10			ns	
$t_h(L)$	LOW Data to Enable				10				
t_{pw}	Enable Pulse Width				15			ns	
t_{ZH}	OE to Y_i					15	28	ns	
t_{ZL}						25	36		
t_{HZ}	OE to Y_i					12	20	ns	$C_L = 5\text{pF}$ $R_L = 667\Omega$
t_{LZ}						15	25		

Am25LS ONLY

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$			
t_{PLH}	Enable to Output					ns	$C_L = 45\text{pF}$ $R_L = 667\Omega$
t_{PHL}							
t_{PLH}	Data Input to Output					ns	
t_{PHL}							
$t_s(H)$	HIGH Data to Enable					ns	
$t_s(L)$	LOW Data to Enable						
$t_h(H)$	HIGH Data to Enable					ns	
$t_h(L)$	LOW Data to Enable						
t_{pw}	Enable Pulse Width					ns	
t_{ZH}	OE to Y_i					ns	
t_{ZL}							
t_{HZ}	OE to Y_i					ns	$C_L = 5\text{pF}$ $R_L = 667\Omega$
t_{LZ}							

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.



Am25LS374 • Am54LS/74LS374

8-Bit Register With Three-State Outputs

DISTINCTIVE CHARACTERISTICS

- Eight-bit, high speed parallel registers
- Positive, edge-triggered, D-type flip-flops
- Buffered common clock and buffered common three-state control
- Am25LS devices offer the following improvements over Am54/74LS
 - 50mV lower V_{OL} at $I_{OL} = 8\text{mA}$
 - Twice the fan-out over military range
 - 440 μA source current at HIGH output
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am25LS374 and Am54LS/74LS374 are eight-bit registers built using advanced Low-Power Schottky technology. These registers consist of eight D-type flip-flops with a buffered common clock and a buffered three-state output control. When the output enable (\overline{OE}) input is LOW, the eight outputs are enabled. When the \overline{OE} input is HIGH, the outputs are in the three-state condition.

Input data meeting the set-up and hold time requirements of the D inputs is transferred to the Y outputs on the LOW-to-HIGH transition of the clock input.

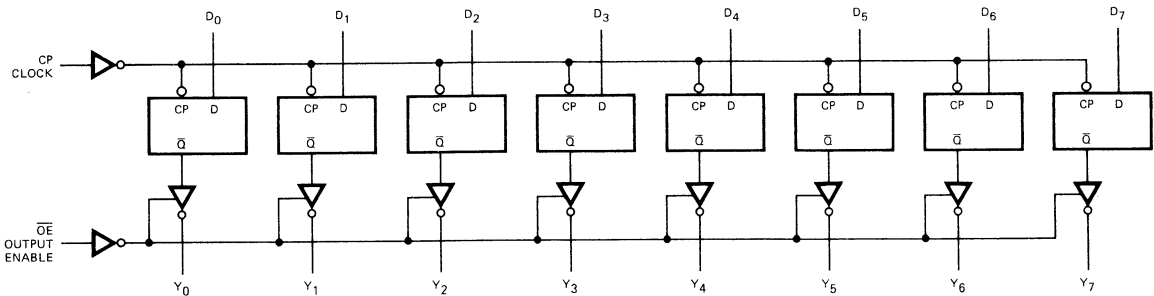
The device is packaged in a space-saving (0.3-inch row spacing) 20-pin package.

Note: The Advanced Micro Devices: LS374 products were designed prior to publication of data sheets by T.I. Review specifications for possible differences.

Note: An inverting version of this device, to be called Am54LS/74LS534, is also in development.

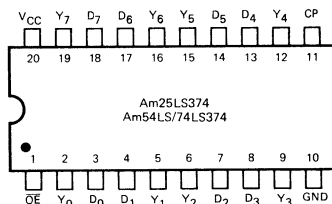
LOGIC DIAGRAM

Am25LS/54LS/74LS374



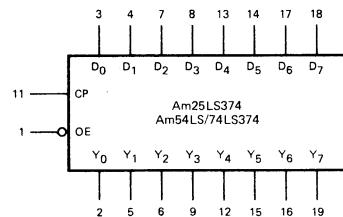
Outputs Y_0 through Y_7 are inverted on the Am25LS/54LS/74LS534.

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



$V_{CC} = \text{Pin } 20$
 $GND = \text{Pin } 10$

3

Am25LS/54LS/74LS374

Am25LS374

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } 70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25V

MIL $T_A = -55^\circ\text{C to } 125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -1.0\text{mA, MIL}$	2.4	3.4		Volts
			$I_{OH} = -2.6\text{mA, COM'L}$	2.4	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$			0.4	Volts
			$I_{OL} = 8.0\text{mA}$			0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$				-0.36	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$				20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$				0.1	mA
I_{OZ}	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$			-20	μA
			$V_O = 2.7\text{V}$			20	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$			27	45	mA

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. All outputs open; all D_i inputs and $\overline{OE} = 4.5\text{V}$. Apply momentary ground, then 4.5V to clock input.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am54LS/74LS374

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 V
 MIL $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -1.0\text{mA}$	MIL	2.4	3.4	Volts	
			$I_{OH} = -2.6\text{mA}$	COM'L	2.4	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	All, $I_{OL} = 4.0\text{mA}$			0.4	Volts	
			74LS only, $I_{OL} = 8.0\text{mA}$			0.5		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs			2.0		Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		MIL		0.7	Volts	
				COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$				-0.4	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$				20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$				0.1	mA	
I_{OZ}	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$		$V_O = 0.5\text{V}$		-20	μA	
				$V_O = 2.4\text{V}$		20		
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$			-15	-100	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$				27	45	mA

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. All outputs open; all D_i inputs and $\overline{OE} = 4.5\text{V}$. Apply momentary ground, then 4.5V to clock input.

DEFINITION OF FUNCTIONAL TERMS

 D_i The D flip-flop data inputs.

CP Clock Pulse for the register. Enters data on the LOW-to-HIGH transition.

 Y_i The register three-state outputs. \overline{OE} Output Control. An active-LOW three-state control used to enable the outputs. A HIGH level input forces the outputs to the high impedance (off) state.

FUNCTION TABLE

FUNCTION	INPUTS			INTERNAL	OUTPUTS
	\overline{OE}	Clock	D_i	Q_i	Y_i
Hi-Z	H	L	X	NC	Z
	H	H	X	NC	Z
LOAD REGISTER	L	\uparrow	L	L	L
	L	\uparrow	H	H	H
	H	\uparrow	L	L	Z
	H	\uparrow	H	H	Z

H = HIGH

L = LOW

X = Don't Care

NC = No Change

Z = High Impedance

 \uparrow = LOW-to-HIGH transition

Am25LS/54LS/74LS374

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Clock to Y_i		18	28			28	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			22	37			37		
t_{PW}	Clock Pulse Width	LOW	25		25			ns	
		HIGH	20		20				
t_s	Data	20			20			ns	
t_h	Data	10	1		10			ns	
t_{ZH}	\overline{OE} to Y_i		11	14			28	ns	
t_{ZL}			14	21			36		
t_{HZ}	\overline{OE} to Y_i		20	30			29	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{LZ}			25	36			35		
f_{max}	Maximum Clock Frequency (Note 1)	30	45		30			MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

Am25LS ONLY SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

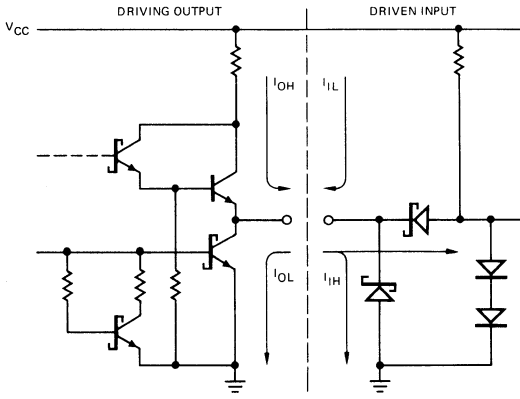
Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to Y_i		36		44	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			47		57		
t_{PW}	Clock Pulse Width	LOW	30	35		ns	
		HIGH	25	30			
t_s	Data	15		20		ns	
t_h	Data	12		15		ns	
t_{ZH}	\overline{OE} to Y_i		20		25	ns	
t_{ZL}			30		39		
t_{HZ}	\overline{OE} to Y_i		35		40	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{LZ}			39		42		
f_{max}	Maximum Clock Frequency (Note 1)	25		20		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

ORDERING INFORMATION

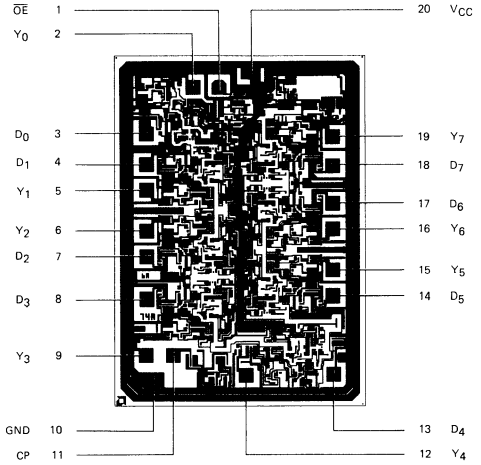
Package Type	Temperature Range	Am25LS374 Order Number	Am54LS/74LS374 Order Number
Molded DIP	0°C to $+70^\circ\text{C}$	AM25LS374PC	SN74LS374N
Hermetic DIP	0°C to $+70^\circ\text{C}$	AM25LS374DC	SN74LS374J
Dice	0°C to $+70^\circ\text{C}$	AM25LS374XC	SN74LS374X
Hermetic DIP	-55°C to $+125^\circ\text{C}$	AM25LS374DM	SN54LS374J
Hermetic Flat Pak	-55°C to $+125^\circ\text{C}$	AM25LS374FM	SN54LS374W
Dice	-55°C to $+125^\circ\text{C}$	AM25LS374XM	SN54LS374X

**Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**



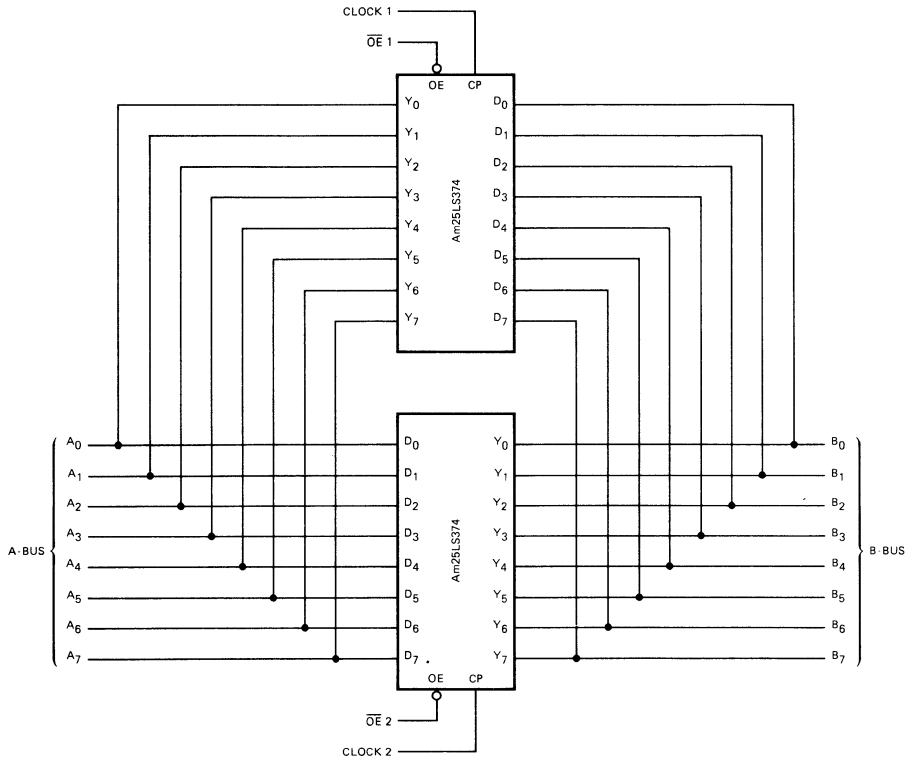
Note: Actual current flow direction shown.

Metallization and Pad Layout



DIE SIZE 0.080" X 0.111"

APPLICATIONS



Two Am25LS374's can be used as a bi-directional bus driver/register. The above connection shows separate clocks and three-state controls.

Am25LS377B • Am54LS/74LS377B

8-Bit Register With Register Enable

DISTINCTIVE CHARACTERISTICS

- Eight-bit, high speed parallel registers
- Positive, edge-triggered, D-type flip-flops
- Buffered common clock and buffered common clock enable
- Am25LS devices offer the following improvements over Am54/74LS
 - 50mV lower V_{OL} at $I_{OL} = 8mA$
 - Twice the fan-out over military range
 - 440 μA source current at HIGH output
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

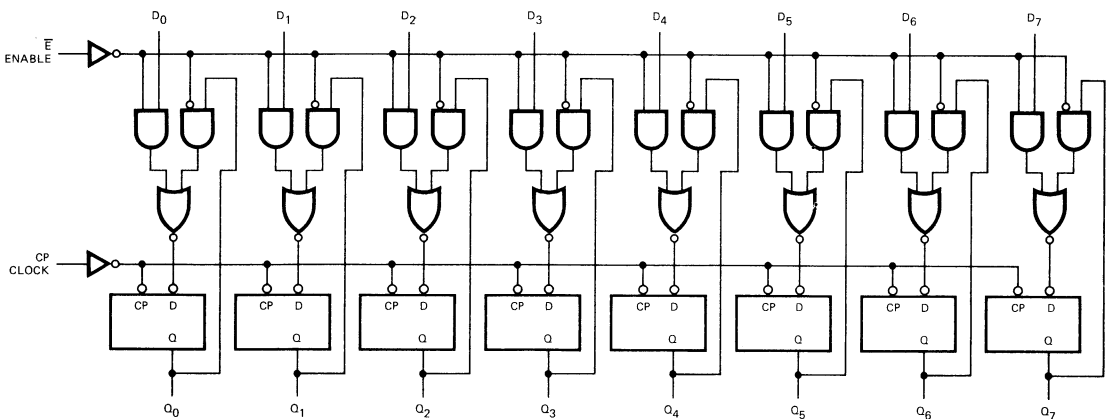
The Am25LS377B and the Am54LS/74LS377B are eight-bit registers built using advanced Low-Power Schottky technology. These registers consist of eight D-type flip-flops with a buffered common clock and a buffered common clock enable.

When the clock enable (\bar{E}) input is LOW, new data is entered into the flip-flop register on the LOW-to-HIGH transition of the clock input. When the (\bar{E}) input is HIGH, the register will retain the present data independent of the clock inputs.

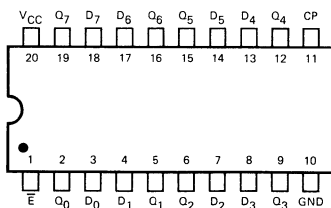
The device is packaged in a space-saving (0.3-inch row spacing) 20-pin package.

Note: The B designation identifies buffered output versions provided to eliminate output commutation.

LOGIC DIAGRAM

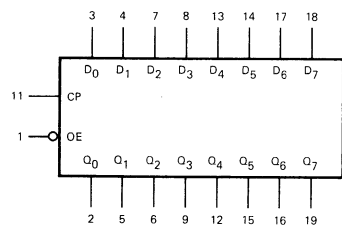


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



$V_{CC} = \text{Pin } 20$
 $GND = \text{Pin } 10$

Am25LS377B

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25V
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -440μA V _{IN} = V _{IH} or V _{IL}	MIL	2.5		Volts
			COM'L	2.7		
V _{OL}	Output LOW Voltage	V _{CC} = MIN. V _{IN} = V _{IH} or V _{IL}	I _{OL} = 4.0mA		0.4	Volts
			I _{OL} = 8.0mA		0.45	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.5	Volts
I _{IL}	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.4V			-0.36	mA
I _{IH}	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			20	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 7.0V			0.1	mA
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.	-15		-85	mA
I _{CC}	Power Supply Current (Note 4)	V _{CC} = MAX.		17	28	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. All outputs open, E = GND, all Di inputs = 4.5V. Apply momentary ground, then 4.5V to clock input.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am54LS/74LS377B

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 V
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}$ $V_{IN} = V_{IH}$ or V_{IL}	MIL	2.5		Volts
			COM'L	2.7		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	All, $I_{OL} = 4\text{mA}$		0.4	Volts
			74LS only, $I_{OL} = 8\text{mA}$		0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.4	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-100	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		17	28	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. All outputs open, E = GND, all D_i inputs = 4.5V. Apply momentary ground, then 4.5V to clock input.

FUNCTION TABLE

INPUTS			OUTPUTS Q_i
\bar{E}	D_i	CP	
H	X	X	NC
L	X	H	NC
L	X	L	NC
L	L	↑	L
L	H	↑	H

H = HIGH

L = LOW

↑ = LOW-to-HIGH Transition

NC = No Change

X = Don't Care

DEFINITION OF FUNCTIONAL TERMS

 D_i The D flip-flop data inputs.

\bar{E} Enable. When the enable is LOW, data on the D_i inputs is transferred to the Q_i outputs on the LOW-to-HIGH clock transition. When the enable is HIGH, the Q_i outputs do not change regardless of the data or clock input transitions.

CP Clock Pulse for the register. Enters data on the LOW-to-HIGH transition.

 Q_i The TRUE register outputs.

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Clock to Output		18	27		18	27	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			23	35		23	35		
t_{PW}	Clock Pulse Width	HIGH	20		20		ns		
		LOW	25		25				
t_s	Data	20			20		ns		
t_h	Data	10			10		ns		
t_s	Clock Enable	Active State	25		25		ns		
		Inactive State	20		20				
t_h	Clock Enable	5			5		ns		
f_{max}	Maximum Clock Frequency (Note 1)	30	40		30	40	ns		

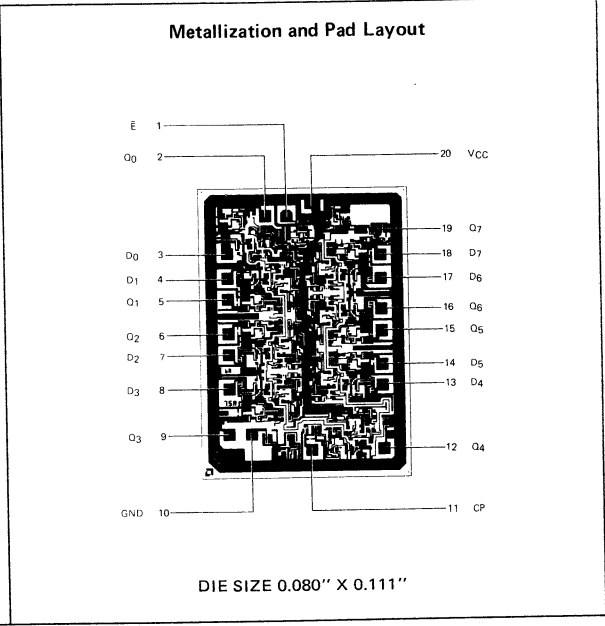
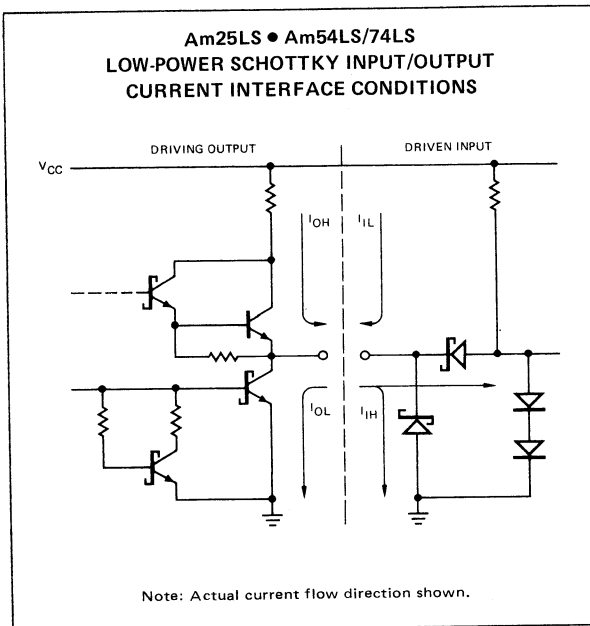
Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

**Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE***

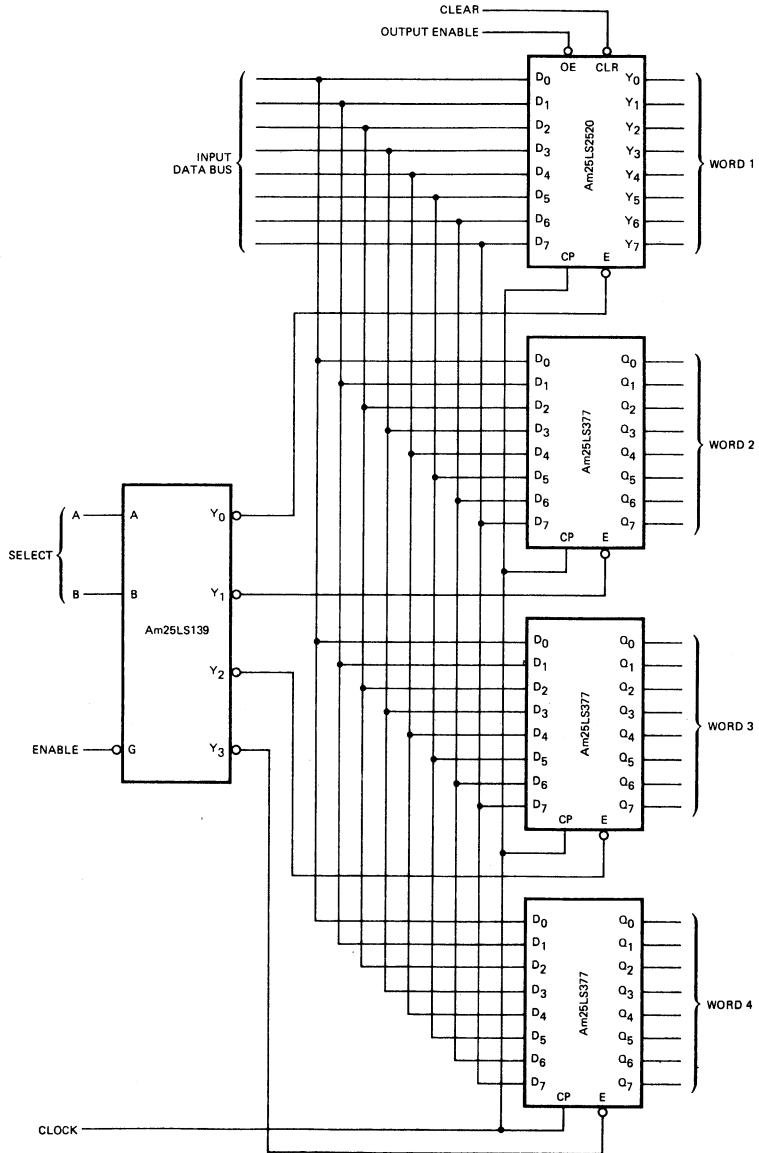
Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to Output		32		37	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
			45		54		
t_{PW}	Clock Pulse Width	HIGH	25	25		ns	
		LOW	25	30			
t_s	Data	20		20		ns	
t_h	Data	12		15		ns	
t_s	Clock Enable	Active	27	30		ns	
		Inactive	22	25			
t_h	Clock Enable	5		5		ns	
f_{max}	Maximum Clock Frequency (Note 1)	25		20		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

3



APPLICATION



Selective Register Loading of Data on Synchronous Clock.

Am25LS378 • Am25LS379 Am54LS/74LS378 • Am54LS/74LS379

Hex/Quad Register With Register Enable

DISTINCTIVE CHARACTERISTICS

- Four-bit and six-bit high-speed parallel registers
- Common clock and common register enable
- Positive edge-triggered D flip-flops
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL} at $I_{OL} = 8\text{mA}$
 - Twice the fan-out over military range
 - 440 μA source current at HIGH output
- 100% product assurance screening to MIL-STD-883 requirements

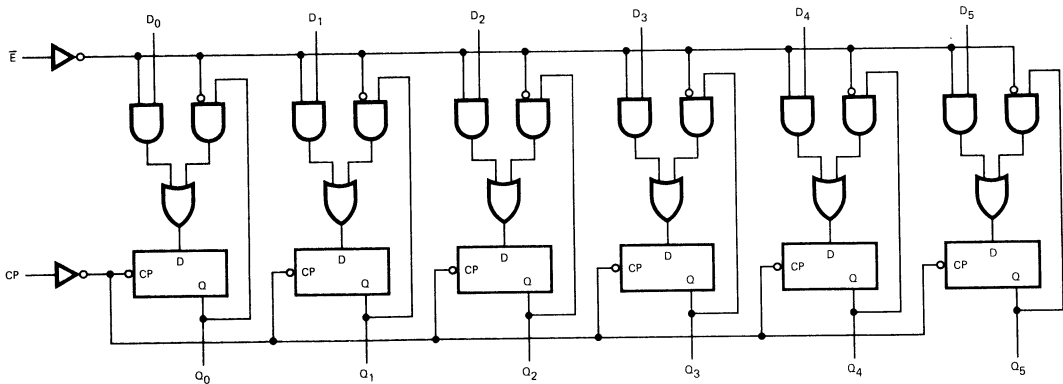
FUNCTIONAL DESCRIPTION

These four-bit and six-bit registers are built using advanced Low-Power Schottky processing. Each register features a buffered common clock as well as a buffered common register enable. These devices are second source versions of the popular Am25LS07 and Am25LS08.

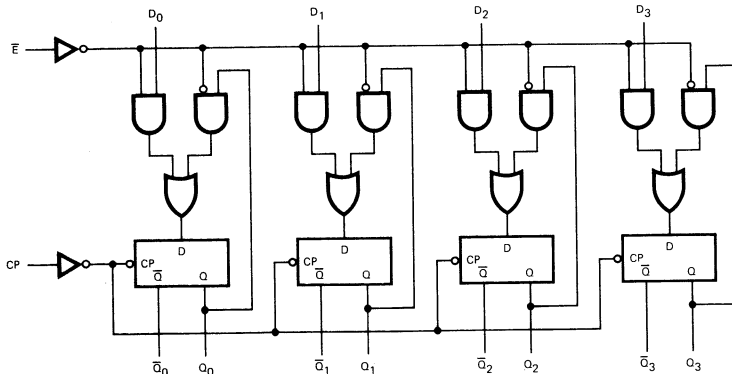
Both registers will find application in digital systems where the information is associated with a logic gating signal. They are ideally suited for a microprogrammed machine where a microprogram control bit provides the register enable signal. When the register enable is LOW, data on the D inputs is stored in the register on the LOW-to-HIGH transition of the clock. When the enable input is HIGH, the register will not change state regardless of the clock or data input transitions.

LOGIC DIAGRAMS

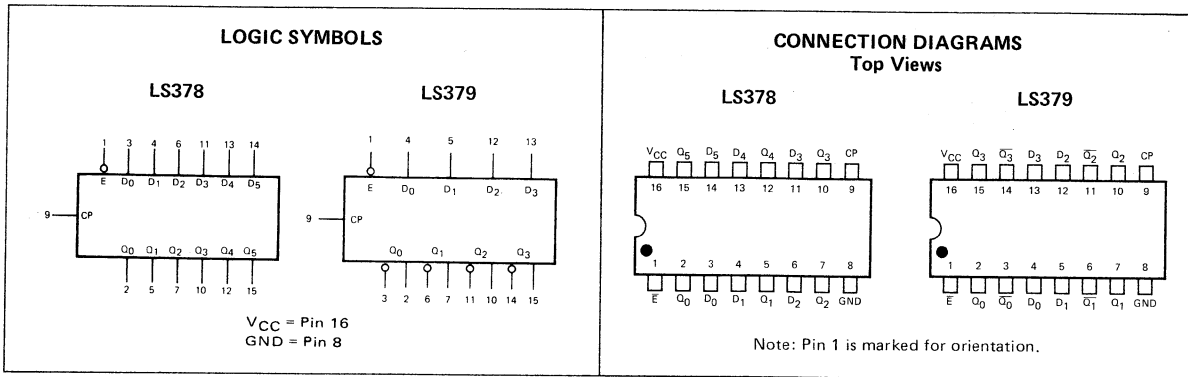
Am25LS378 • Am54LS/74LS378



Am25LS379 • Am54LS/74LS379



3



Am25LS378 • Am25LS379

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75V MAX. = 5.25V)
MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50V MAX. = 5.50V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4	Volts
			COM'L	2.7	3.4	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.4	Volts
			$I_{OL} = 8.0\text{mA}$		0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	Clock, \bar{E}		-0.36	mA
			Others		-0.24	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	Clock		20	μA
			Others		14	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$	LS378		16	mA
			LS379		11	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
4. Outputs open; enable grounded; data inputs at 4.5V, measured after a momentary ground, then 4.5V applied to the clock input.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am54LS/74LS378 • Am54LS/74LS379

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ (MIN. = 4.75 V MAX. = 5.25 V)MIL $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ (MIN. = 4.50 V MAX. = 5.50 V)

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}$ $V_{IN} = V_{IH}$ or V_{IL}	MIL	2.5	3.4	Volts
			COM'L	2.7	3.4	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH}$ or V_{IL}	All, $I_{OL} = 4.0\text{mA}$		0.4	Volts
			74LS only, $I_{OL} = 8\text{mA}$		0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.4	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-100	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$	LS378	16	22	mA
			LS379		11	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Outputs open; enable grounded; data inputs at 4.5V, measured after a momentary ground, then 4.5V applied to a clock input.

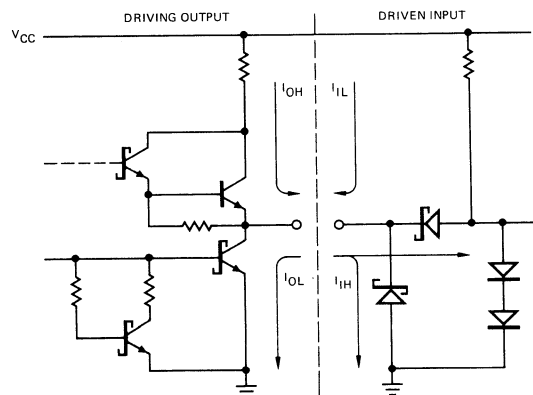
DEFINITION OF FUNCTIONAL TERMS

 D_i The D flip-flop data inputs. E Enable. When the enable is LOW, data on the D_i inputs is transferred to the Q_i outputs on the LOW-to-HIGH clock transition. When the enable is HIGH, the Q_i outputs do not change regardless of the data or clock input transitions. CP Clock Pulse for the register. Enters data on the LOW-to-HIGH transition. Q_i The TRUE register outputs. \bar{Q}_i The complement register outputs

FUNCTION TABLE

Inputs			Outputs	
\bar{E}	D_i	CP	Q_i	\bar{Q}_i
H	X	X	NC	NC
L	X	H	NC	NC
L	X	L	NC	NC
L	L	↑	L	H
L	H	↑	H	L

H = HIGH
 L = LOW
 ↑ = LOW-to-HIGH Transition
 \bar{Q}_i on LS379 Only
 NC = No Change
 X = Don't Care

Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS

Note: Actual current flow direction shown.

Am25LS/54LS/74LS378/379

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Clock to Output		13	20		17	27	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			13	20		18	27		
tpw	Clock Pulse Width	17			20				
t_s	Data	20			20				
t_h	Data	5.0			5.0				
t_s	Clock Enable	25			25				
t_h	Clock Enable	5.0			5.0				
f_{max}	Maximum Clock Frequency (Note 1)	40	65		30	40		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

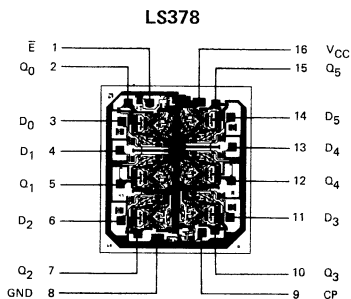
Am25LS ONLY

SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

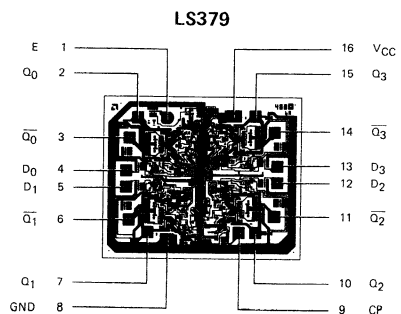
Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to Output					ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}		30		35			
tpw	Clock Pulse Width	26		30		ns	
t_s	Data	30		35		ns	
t_h	Data	11		12		ns	
t_s	Clock Enable	33		38		ns	
t_h	Clock Enable	11		12		ns	
f_{max}	Maximum Clock Frequency (Note 1)	30		26		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

Metallization and Pad Layout



DIE SIZE 0.075" X 0.084"

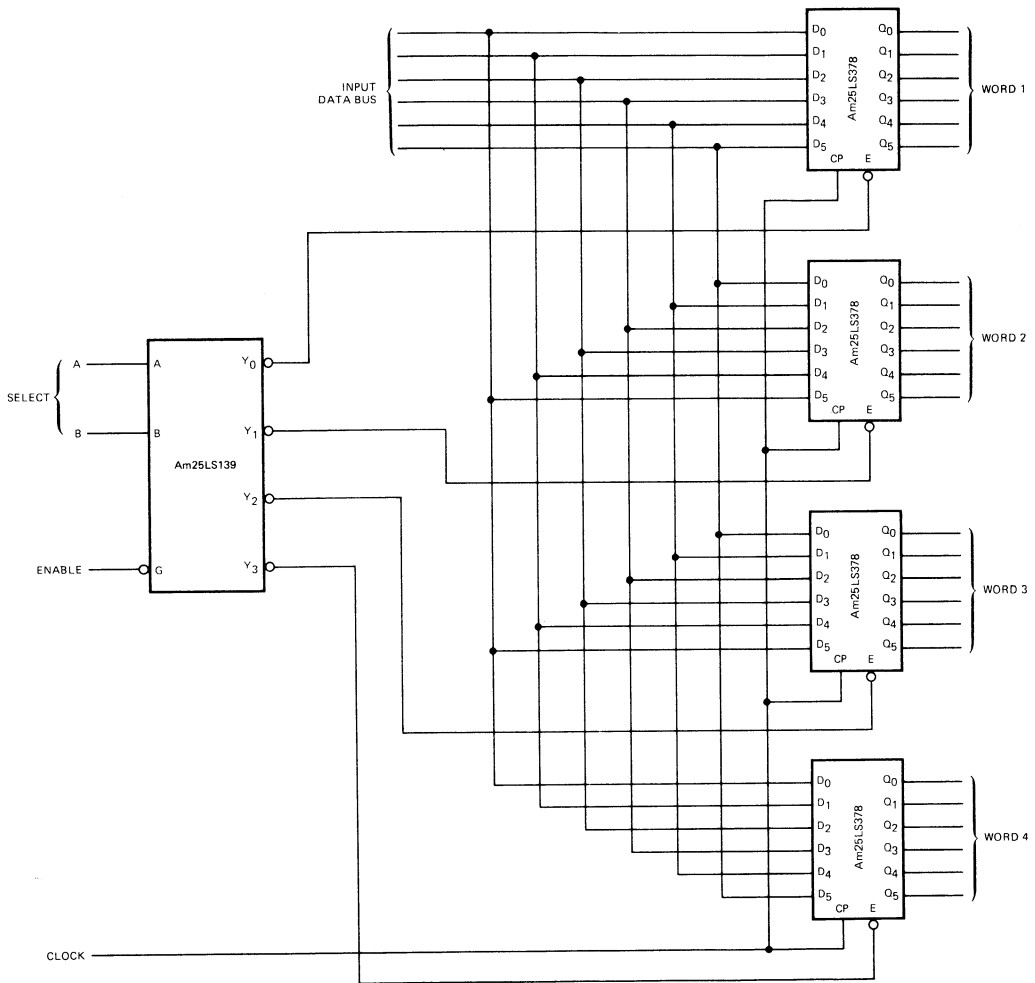


DIE SIZE 0.061" X 0.075"

ORDERING INFORMATION

Package Type	Temperature Range	Am25LS378 Order Number	Am25LS379 Order Number	Am54LS/74LS378 Order Number	Am54LS/74LS379 Order Number
Molded DIP	0°C to +70°C	AM25LS378PC	AM25LS379PC	SN74LS378N	SN74LS379N
Hermetic DIP	0°C to +70°C	AM25LS378DC	AM25LS379DC	SN74LS378J	SN74LS379J
Dice	0°C to +70°C	AM25LS378XC	AM25LS379XC	SN74LS378X	SN74LS379X
Hermetic DIP	-55°C to +125°C	AM25LS378DM	AM25LS379DM	SN54LS378J	SN54LS379J
Hermetic Flat Pak	-55°C to +125°C	AM25LS378FM	AM25LS379FM	SN54LS378W	SN54LS379W
Dice	-55°C to +125°C	AM25LS378XM	AM25LS379XM	SN54LS378X	SN54LS379X

APPLICATION



Selective Register Loading of Data on Synchronous Clock.

3

Am25LS381 • Am54LS/74LS381 Am25LS2517

Arithmetic Logic Unit/Function Generator

DISTINCTIVE CHARACTERISTICS

- Three arithmetic functions
- Three logic functions
- Preset and clear functions
- Space-saving 20-pin package
- Carry output (C_{n+4}) and overflow (OVR) outputs on Am25LS2517
- Generate and propagate outputs for full lookahead carry on Am25LS381
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL} at $I_{OL} = 8\text{mA}$
 - Twice the fan-out over military range
 - 440 μA source current at HIGH output
- 100% product assurance testing to MIL-STD-883 requirements

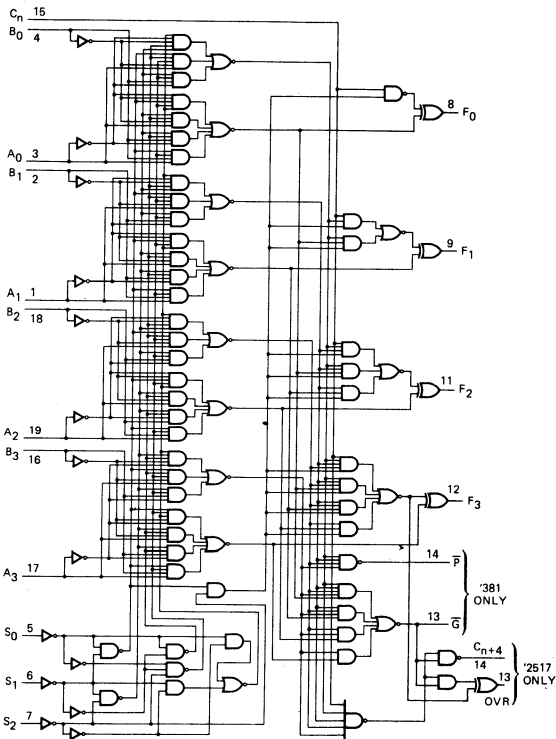
FUNCTIONAL DESCRIPTION

The Am25LS381 and Am54LS/74LS381 are arithmetic logic units (ALU)/function generators that perform three arithmetic operations and three logic operations on two 4-bit words. The device can also output forced 0000 (clear) or 1111 (preset). These eight operations are selected using three function select inputs S_0 , S_1 and S_2 as shown in the function table. Full carry look ahead is used over the four-bit field within the device. When devices are cascaded, multi-level full carry look-ahead is implemented using a '182 carry look ahead generator and the \bar{G} and \bar{P} outputs on the Am25LS381 or Am54LS/74LS381. The device is packaged in a space-saving (0.3-inch row spacing) 20-pin package. If the C_{n+4} carry output function is required, the Am25LS2517 should be used.

The Am25LS381 is a high-performance version of the Am54LS/74LS381. Improvements include faster a. c. specifications, higher noise margin and twice the fan-out over the military temperature range.

The Am25LS2517 is an arithmetic logic unit (ALU)/function generator that performs three arithmetic operations and three logic operations on two 4-bit words. The device can also force output 0000 (clear) or 1111 (preset). These eight operations are selected using three function select inputs S_0 , S_1 and S_2 as shown in the function table. Full carry look-ahead is used over the four-bit field within the device. When devices are cascaded, the carry output (C_{n+4}) is connected to the carry input (C_n) of the next device. The Am25LS2517 can also detect two's complement overflow. The overflow output (OVR) is defined logically as $C_{n+3} \oplus C_{n+4}$.

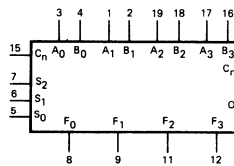
LOGIC DIAGRAM



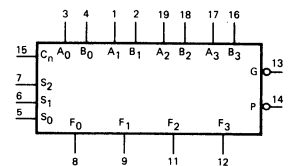
Note: The Advanced Micro Devices' LS381 products were designed prior to publication of data sheets by T.I. Review specifications for possible differences. Am25LS2517 has been second sourced as the 54/74LS382.

LOGIC SYMBOLS

Am25LS2517



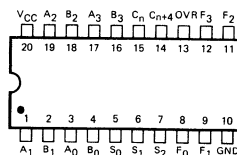
Am25LS381
Am54LS/74LS381



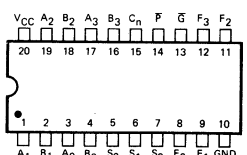
$V_{CC} = \text{Pin } 20$
 $GND = \text{Pin } 10$

CONNECTION DIAGRAMS Top Views

Am25LS2517



Am25LS381
Am54LS/74LS381



Note: Pin 1 is marked for orientation.

Am25LS381 • Am25LS2517

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25VMIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units		
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4		Volts	
			COM'L	2.7	3.4			
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$			0.4	Volts	
			$I_{OL} = 8.0\text{mA}$			0.45		
			$\bar{G}, I_{OL} = 16\text{mA}$			0.55		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts		
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts	
			COM'L			0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts		
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	Any S			-0.36	mA	
			Any A or B			-1.44		
			'LS381, C_n			-1.08		
			'LS2517, C_n			-1.44		
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	Any S			20	μA	
			Any A or B			80		
			'LS381, C_n			60		
			'LS2517, C_n			80		
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$	Any S			0.1	mA	
			Any A or B			0.4		
		$V_{CC} = \text{MAX.}, V_{IN} = 5.5\text{V}$	'LS381, C_n			0.3		
			'LS2517, C_n			0.4		
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA		
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$	MIL	Am25LS381			40	mA
				Am25LS2517			43	
			COM'L	Am25LS381		25	43	
				Am25LS2517		27	47	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. Test conditions: LS381: $S_0 = S_1 = S_2 = \text{GND}$, all other inputs open.LS2517: $S_0 = C_n = \text{open}$, all other inputs = GND.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	$-65^\circ\text{C to } +150^\circ\text{C}$
Temperature (Ambient) Under Bias	$-55^\circ\text{C to } +125^\circ\text{C}$
Supply Voltage to Ground Potential Continuous	$-0.5\text{V to } +7.0\text{V}$
DC Voltage Applied to Outputs for High Output State	$-0.5\text{V to } +V_{CC} \text{ max.}$
DC Input Voltage (Except Am25LS2517, C_n input = 5.5V)	$-0.5\text{V to } +7.0\text{V}$
DC Output Current, Into Outputs	30mA
DC Input Current	$-30\text{mA to } +5.0\text{mA}$

Am54LS/74LS381

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 VMIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4	Volts	
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4\text{mA}$			0.4	Volts
			74LS only, $I_{OL} = 8\text{mA}$			0.5	
			$\bar{P}, I_{OL} = 8.0\text{mA}$			0.5	
			$\bar{G}, I_{OL} = 16\text{mA}$			0.65	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current (Note 5)	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	Any S		-0.4	mA	
			Others		-1.6		
I_{IH}	Input HIGH Current (Note 5)	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	Any S		20	μA	
			Others		80		
I_I	Input HIGH Current (Note 5)	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$	Any S		0.1	mA	
			Others		0.4		
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-100	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		25	43	mA	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Test conditions: LS381: $S_0 = S_1 = S_2 = \text{GND}$, all other inputs open.
 LS2517: $S_0 = C_n = \text{open}$, all other inputs = GND.
 5. Limits chosen by AMD based on SN54S/74S381, T.I. LS data unavailable.

DEFINITION OF FUNCTIONAL TERMS

- A_0, A_1, A_2, A_3 The A data inputs.
 B_0, B_1, B_2, B_3 The B data inputs.
 S_0, S_1, S_2, S_3 The control inputs used to determine the arithmetic or logic function performed.
 F_0, F_1, F_2, F_3 The data outputs of the ALU.
 C_n The carry-in input of the ALU.
 C_{n+4} The carry-look-ahead output of the four-bit input field.
 \bar{G} The carry-generate output for use in multi-level look-ahead schemes.
 \bar{P} The carry-propagate output for use in multi-level look-ahead schemes.
OVR Overflow. This pin is logically the Exclusive-OR of the carry-in and carry-out of the MSB of the ALU. At the most significant end of the word, this pin indicates that the result of an arithmetic two's complement operation has overflowed into the sign-bit.

FUNCTION TABLE

Selection			Arithmetic/Logic Operation
S_2	S_1	S_0	
L	L	L	Clear
L	L	H	B Minus A
L	H	L	A Minus B
L	H	H	A Plus B
H	L	L	$A \oplus B$
H	L	H	$A + B$
H	H	L	AB
H	H	H	Preset

H = High Level, L = Low Level
 See Truth Table for full description.

SWITCHING CHARACTERISTICS

 $(T_A = +25^\circ\text{C}, V_{CC} = 5.0\text{V})$

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t _{PLH}	C _n to F _i		14	19			26	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			16	23			30		
t _{PLH}	A _i or B _i to F _i		16	24			30	ns	
t _{PHL}			23	35			40		
t _{PLH}	S _i to F _i		20	30			35	ns	
t _{PHL}			25	37			40		
t _{PLH}	A _i or B _i to \overline{G} (LS381 Only)		20	27			35	ns	
t _{PHL}			15	22			30		
t _{PLH}	A _i or B _i to \overline{P} (LS381 Only)		17	24			34	ns	
t _{PHL}			15	23			30		
t _{PLH}	S _i to \overline{G} or \overline{P} (LS381 Only)		32	48			55	ns	
t _{PHL}			23	35			42		
t _{PLH}	A _i or B _i to OVR (LS2517 Only)		23	34			—	ns	
t _{PHL}			24	36			—		
t _{PLH}	A _i or B _i to C _{n+4} (LS2517 Only)		21	32			—	ns	
t _{PHL}			24	36			—		
t _{PLH}	S _i to OVR or C _{n+4} (LS2517 Only)		27	41			—	ns	
t _{PHL}			37	55			—		
t _{PLH}	C _n to C _{n+4} (LS2517 Only)		14	21			—	ns	
t _{PHL}			15	22			—		
t _{PLH}	C _n to OVR (LS2517 Only)		15	22			—	ns	
t _{PHL}			15	22			—		

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Am25LS ONLY
SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	C _n to F _i		27		30	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			35		42		
t _{PLH}	A _i or B _i to F _i		32		36	ns	
t _{PHL}			44		50		
t _{PLH}	S _i to F _i		38		42	ns	
t _{PHL}			48		55		
t _{PLH}	A _i or B _i to \overline{G} (LS381 Only)		37		40	ns	
t _{PHL}			31		36		
t _{PLH}	A _i or B _i to \overline{P} (LS381 Only)		34		39	ns	
t _{PHL}			34		42		
t _{PLH}	S _i to \overline{G} or \overline{P} (LS381 Only)		57		63	ns	
t _{PHL}			47		55		
t _{PLH}	A _i or B _i to OVR (LS2517 Only)		41		45	ns	
t _{PHL}			47		55		
t _{PLH}	A _i or B _i to C _{n+4} (LS2517 Only)		38		40	ns	
t _{PHL}			46		52		
t _{PLH}	S _i to OVR or C _{n+4} (LS2517 Only)		52		60	ns	
t _{PHL}			66		75		
t _{PLH}	C _n to C _{n+4} (LS2517 Only)		28		32	ns	
t _{PHL}			28		30		
t _{PLH}	C _n to OVR (LS2517 Only)		30		35	ns	
t _{PHL}			28		30		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

Am25LS/54LS/74LS381
TEST TABLE

Path		S ₀	S ₁	S ₂	C _n	Same Bit		Other Data Bits		Output Waveform
In	Out					4.5V	GND	4.5V	GND	
C _n	Any F	1	0	0	—	—	—	All A's & B's	—	out-of-phase
C _n	F _i	1	0	0	—	B _i	A _i	All A's & B's	—	in-phase
A _i	\overline{G}	1	1	0	X	B _i	—	All B's	All A's	out-of-phase
B _i	\overline{G}	1	1	0	X	A _i	—	All B's	All A's	out-of-phase
A _i	\overline{P}	X	X	1	X	B _i	—	All A's & B's	—	out-of-phase
B _i	\overline{P}	1	1	0	X	A _i	—	All B's	All A's	out-of-phase
A _i	F _i	0	1	0	0	—	B _i	—	A's & B's	out-of-phase
A _i	F _i	0	1	0	1	—	B _i	—	A's & B's	in-phase
B _i	F _i	0	1	0	0	—	A _i	—	A's & B's	out-of-phase
B _i	F _i	0	1	0	1	—	A _i	—	A's & B's	in-phase
A _i	F _{i+1}	0	1	0	1	B _i	—	A's & B's	—	out-of-phase
B _i	F _{i+1}	1	0	0	1	A _i	—	A's & B's	—	out-of-phase
S ₀	F _i	—	0	0	1	B _i	A _i	All B's	All A's	in-phase
S ₀	\overline{G}	—	1	0	X	—	—	A's & B's	—	out-of-phase
S ₀	\overline{P}	—	1	0	X	—	—	All B's	All A's	out-of-phase
S ₁	F _i	0	—	0	1	A _i	B _i	All A's	All B's	in-phase
S ₁	\overline{G}	1	—	0	X	—	—	A's & B's	—	out-of-phase
S ₁	\overline{P}	1	—	0	X	—	—	All A's	All B's	out-of-phase
S ₂	F _i	0	1	—	1	A _i	B _i	All A's	All B's	in-phase
S ₂	\overline{G}	1	1	—	X	—	—	A's & B's	—	in-phase
S ₂	\overline{P}	1	1	—	X	—	—	All A's	All B's	out-of-phase

X = Don't care

TRUTH TABLE

FUNCTION	INPUTS						OUTPUTS							
	S ₀	S ₁	S ₂	C _n	A _n	B _n	F ₀	F ₁	F ₂	F ₃	\overline{G}	\overline{P}		
CLEAR	0	0	0	X	X	X	0	0	0	0	0	0		
B MINUS A	1	0	0	0	0	0	1	1	1	1	1	0		
				0	0	1	0	1	1	1	1	0	0	
				0	1	0	0	0	0	0	0	1	1	0
				0	1	1	1	1	1	1	1	1	1	0
				1	0	0	0	0	0	0	0	0	1	0
				1	0	1	1	1	1	1	1	1	1	0
				1	1	0	1	0	0	0	0	0	1	1
A MINUS B	0	1	0	0	0	0	1	1	1	1	1	0		
				0	0	1	0	0	0	0	1	1	0	
				0	1	0	0	1	1	1	1	1	0	0
				0	1	1	1	1	1	1	1	1	1	0
				1	0	0	0	0	0	0	0	0	1	0
				1	0	1	1	0	0	0	0	0	1	1
				1	1	0	1	1	1	1	1	1	1	0
A PLUS B	1	1	0	0	0	0	0	0	0	0	1	1		
				0	0	1	1	1	1	1	1	1	0	
				0	1	0	1	1	1	1	1	1	1	0
				0	1	1	0	1	1	1	1	1	0	0
				1	0	0	1	0	0	0	0	0	1	1
				1	0	1	0	0	0	0	0	0	1	0
				1	1	0	0	0	0	0	0	0	1	0
A ⊕ B	0	0	1	X	0	0	0	0	0	0	0	0		
				X	0	1	1	1	1	1	1	1		
				X	1	0	1	1	1	1	1	1		
				X	1	1	0	0	0	0	0	0		
A + B	1	0	1	X	0	0	0	0	0	0	0	0		
				X	0	1	1	1	1	1	1	1		
				X	1	0	1	1	1	1	1	1		
				X	1	1	1	1	1	1	1	0		
AB	0	1	1	X	0	0	0	0	0	0	0	0		
				X	0	1	0	0	0	0	1	1		
				X	1	0	0	0	0	0	0	0		
				X	1	1	1	1	1	1	1	0		
PRESET	1	1	1	X	0	0	1	1	1	1	1	1		
				X	0	1	1	1	1	1	1	1		
				X	1	0	1	1	1	1	1	1		
				X	1	1	1	1	1	1	1	0		

**Am25LS2517
TEST TABLE**

Path		S ₀	S ₁	S ₂	C _n	Same Bit		Other Data Bits		Output Waveform
In	Out					4.5 V	GND	4.5 V	GND	
C _n	Any F	1	0	0	—	—	—	A's & B's	None	out-of-phase
C _n	F _i	1	0	0	—	B _i	A _i	A's & B's	None	in-phase
A _i	F _i	0	1	0	0	—	B _i	None	A's & B's	out-of-phase
A _i	F _i	0	1	0	1	—	B _i	None	A's & B's	in-phase
A _i	OVRF	0	1	1	1	B _i	—	A's & B's	None	in-phase
A _i	C _{n+4}	0	1	1	1	B _i	—	A's & B's	None	in-phase
B _i	F _i	0	1	0	0	—	A _i	None	A's & B's	out-of-phase
B _i	F _i	0	1	0	1	—	A _i	—	A's & B's	in-phase
B _i	OVRF	0	1	1	0	A _i	—	A's & B's	None	out-of-phase
B _i	C _{n+4}	0	1	1	0	A _i	—	A's & B's	None	out-of-phase
A _i	F _{i+1}	0	1	0	1	B _i	—	A's & B's	None	out-of-phase
B _i	F _{i+1}	1	0	0	1	A _i	—	A's & B's	None	out-of-phase
S ₀	F _i	—	0	0	1	B _i	A _i	All B's	All A's	in-phase
S ₀	OVRF	—	1	1	0	—	—	A's & B's	None	out-of-phase
S ₀	C _{n+4}	—	1	1	0	—	—	None	A's & B's	out-of-phase
S ₁	F _i	0	—	0	1	A _i	B _i	All A's	All B's	in-phase
S ₁	OVRF	0	—	1	X	—	—	None	A's & B's	in-phase
S ₁	C _{n+4}	0	—	1	X	—	—	None	A's & B's	in-phase
S ₂	F _i	0	1	—	1	A _i	B _i	All A's	All B's	in-phase
S ₂	OVRF	0	1	—	0	—	—	None	A's & B's	in-phase
S ₂	C _{n+4}	0	1	—	0	—	—	None	A's & B's	in-phase

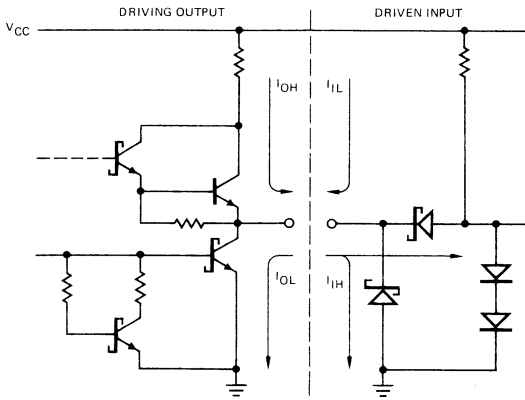
X = Don't care

TRUTH TABLE

FUNCTION	INPUTS					OUTPUTS						
	S ₀	S ₁	S ₂	C _n	A _n	B _n	F ₀	F ₁	F ₂	F ₃	OVR	C _{n+4}
CLEAR	0	0	0	1	X	X	0	0	0	0	1	1
					X	X	0	0	0	0	0	1
					0	0	0	1	1	1	1	0
					0	0	1	0	1	1	1	0
					0	1	0	0	0	0	0	0
					0	1	1	1	1	1	1	0
					1	0	0	0	0	0	0	1
					1	0	1	1	1	1	1	0
					1	1	0	1	0	0	0	0
					1	1	1	0	0	0	0	1
					0	0	0	1	1	1	1	0
					0	0	1	1	1	1	1	0
					0	1	0	1	1	1	1	0
					0	1	1	0	1	1	1	0
					1	0	0	1	0	0	0	0
					1	0	1	0	0	0	0	1
					1	1	0	1	1	1	1	0
					1	1	1	0	0	0	0	1
					0	0	0	0	0	0	0	0
					0	0	1	1	1	1	1	0
					0	1	0	1	1	1	1	0
					0	1	1	0	0	0	0	1
					1	0	0	0	0	0	0	0
					1	0	1	1	1	1	1	0
					1	1	0	1	1	1	1	0
					1	1	1	1	1	1	1	1
					0	0	0	1	1	1	1	0
					0	0	1	1	1	1	1	0
					0	1	0	1	1	1	1	0
					0	1	1	1	1	1	1	0
					1	0	0	1	1	1	1	0
					1	0	1	1	1	1	1	0
					1	1	0	1	1	1	1	0
					1	1	1	1	1	1	1	1

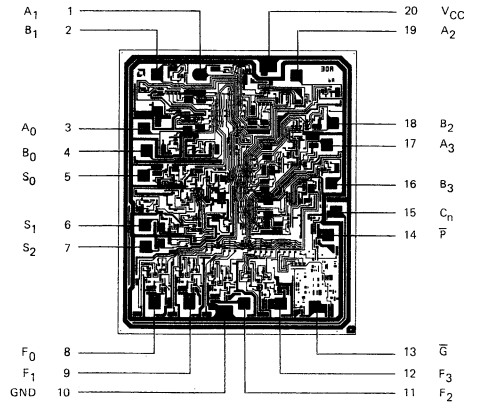
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Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

Metallization and Pad Layout

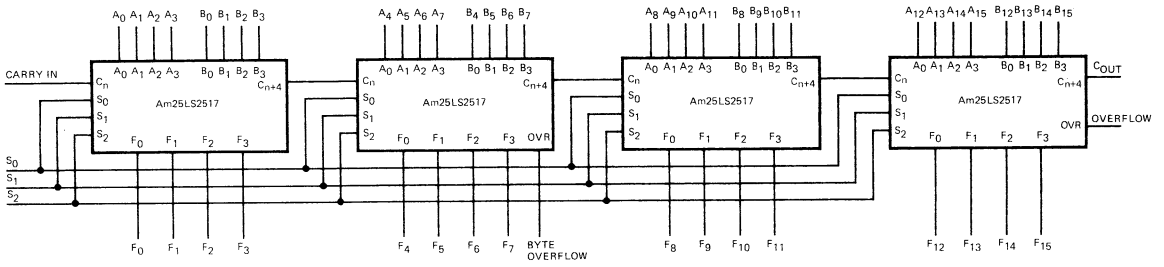


DIE SIZE 0.091" X 0.108"

USER NOTES

1. Throughout this data sheet, the active HIGH input and output terminology has been used.
2. Arithmetic operations are performed on a word basis.
3. Logic operations are performed on a bit basis.
4. Arithmetic in 1's complement notation requires an end around carry.
5. Subtraction in 2's complement notation requires a carry in (C_n = HIGH) for the active HIGH case.

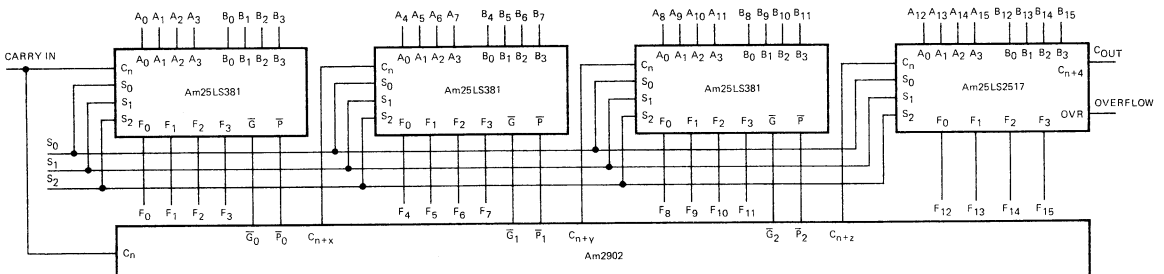
APPLICATIONS



TYPICAL SPEED CALCULATIONS

Path	Output	
	F	C _{n+4} , OVR
A _i or B _j to C _{n+4}	24 ns	24 ns
C _n to C _{n+4}	15 ns	15 ns
C _n to C _{n+4}	15 ns	15 ns
C _n to F _i	16 ns	—
C _n to C _{n+4} , OVR	—	15 ns
16-Bit Speed	70 ns	69 ns

The Am25LS2517 in a 16-Bit Ripple Carry ALU Connection.



TYPICAL SPEED CALCULATIONS

Path	Output	
	F	C _{n+4} , OVR
A _i or B _j to G-bar or P-bar	20 ns*	20 ns*
G-bar _i or P-bar _j to C _{i+j} (Am 2902)	8 ns	8 ns
C _n to F	16 ns	—
C _n to C _{n+4} , OVR	—	15 ns
16-Bit Speed	44 ns	43 ns

* Note that S₁ to G or P may be longer path.

The Am25LS2517 and Am25LS381 in a 16-Bit Carry Lookahead ALU Connection.

UNDERSTANDING THE Am25LS2517 AND THE Am25LS381

By John R. Mick

INTRODUCTION

The heart of most digital arithmetic processors is the arithmetic logic unit (ALU). The ALU can be thought of as a digital subsystem that performs various arithmetic and logic operations on two digital input variables. The Am25LS2517 and the Am25LS381 are Schottky TTL arithmetic logic units/function generators that perform eight arithmetic/logic operations on two four-bit input variables. In most ALU's, speed is generally a key ingredient. Therefore, as much parallelism in the operation of the arithmetic logic unit as possible is desired.

The Am25LS381 ALU is designed to operate with a '182 carry lookahead generator to perform multi-level full carry lookahead over any number of bits. Therefore, the Am25LS381 has both the carry generate and carry propagate outputs required by the '182 carry lookahead generator. The Am25LS2517, on the other hand, does not have the carry generate and carry propagate functions, but rather has the carry output (C_{n+4}) and a two's complement overflow detection signal (OVR) available at the output. The net result is that a very high-speed 16-bit arithmetic logic unit/function generator can be designed and assembled using three Am25LS381's, one Am25LS2517, and one Am2902 (the Am2902 is a high-speed version of the '182 carry lookahead generator).

UNDERSTANDING THE FULL ADDER

The results of an arithmetic operation in any position in a word depends not only on the two-input operand bits at that position, but also on all the lesser significant operand bits of the two input variables. The final result for any bit, therefore, is not available until the carries of all the previous bits have rippled through the logic arrays starting from the least significant bit and propagating through to the most significant bit. A full adder is a device that accepts two individual operand bits at the same binary weight, and also accepts a carry input bit from the next lesser significant weight full adder. The full adder then produces the sum bit for this bit position and also produces a carry bit to be used in the next more significant weight full adder carry input. The truth table for a full adder is

shown in Figure 1. From this truth table, the equations for the full adder:

$$S = A \oplus B \oplus C$$

$$C_0 = AB + BC + AC,$$

where A and B are the input operands to the full adder and C is the carry input into the adder.

The sum output, S, represents the sum of the A and B operand inputs and the carry input. The carry output, C_0 , represents the carry out of this cell and can be used in the next more significant cell of the adder. Full adder cells can be cascaded as depicted in Figure 2 to form a four-bit ripple carry parallel adder.

Inputs			Outputs	
A	B	C	S	C_0
0	0	0	0	0
0	0	1	1	0
0	1	0	1	0
0	1	1	0	1
1	0	0	1	0
1	0	1	0	1
1	1	0	0	1
1	1	1	1	1

Figure 1. Full Adder Truth Table.

Note that once we have cascaded devices as shown in Figure 2, we may wish to discuss the equations for the i-th bit of the adder. In so doing, we might describe the equations of the full adder as follows:

$$S_i = A_i \oplus B_i \oplus C_i$$

$$C_{i+1} = A_i B_i + B_i C_i + A_i C_i$$

where the A_i and B_i are the input operands at the i-th bit, and the C_i is the carry input to the i-th bit. (Note that the equations for this adder are iterative in nature and each depends on the result of the previous lesser significant bits of the adder array.)

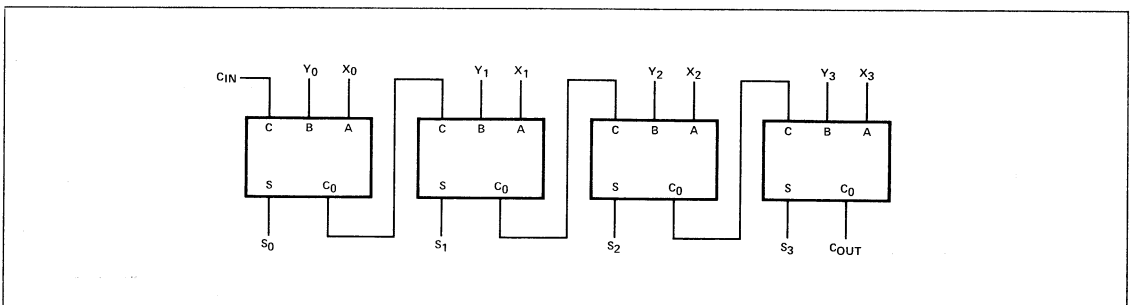


Figure 2. Cascaded Full Adder Cells Connected as a Four-Bit Ripple-Carry Full Adder.

The connection scheme shown in Figure 2 requires a ripple propagation time through each full adder cell. If a 16-bit adder is to be assembled, the carry will have to propagate through all 16 full adder cells. What is desired is some technique for anticipating the carry such that we will not have to wait for a ripple carry to propagate through the entire network. By using some additional logic, such an adder array can be constructed. This type of adder is usually called a carry lookahead adder.

A FOUR-BIT CARRY LOOKAHEAD ADDER

Looking back to the equations developed for i -th bit of an adder, let us now rewrite the carry equation in a slightly different form. When we factor the C_i in this equation, the new equation becomes:

$$C_{i+1} = A_i B_i + C_i (A_i + B_i)$$

From the above equation, let us now define two additional equations. These are:

$$G_i = A_i B_i$$

$$P_i = A_i + B_i$$

With these two new auxiliary equations, we can now rewrite the carry equation for the i -th bit as follows:

$$C_{i+1} = G_i + P_i C_i$$

Note that we have now developed two terms: the P_i term is known as carry propagate and the G_i term is known as carry generate. An anticipated carry can be generated at any stage of the adder by implementing the above equations and using the auxiliary functions P_i and G_i as required.

It is interesting to note that the sum equation can also be written in terms of these two auxiliary equations, P_i and G_i . For this case, the equation is:

$$S_i = (A_i + B_i) (A_i B_i) \oplus C_i$$

The auxiliary function G_i is called carry generate, because if it is true, then a carry is immediately produced for the next adder stage. The function P_i is called carry propagate because it implies there will be a carry into the next stage of the adder if there is a carry into this stage of the adder. That is, G_i causes a carry signal at the i -th stage of the adder to be generated and presented to the next stage of the adder while P_i causes an existing carry at the input to the i -th stage of the adder to propagate to the next stage of the adder.

Let us now write all of the sum and carry equations required for a full four-bit lookahead carry adder.

$$S_0 = A_0 \oplus B_0 \oplus C_0$$

$$S_1 = A_1 \oplus B_1 \oplus [G_0 + P_0 C_0]$$

$$S_2 = A_2 \oplus B_2 \oplus [G_1 + P_1 G_0 + P_1 P_0 C_0]$$

$$S_3 = A_3 \oplus B_3 \oplus [G_2 + P_2 G_1 + P_2 P_1 G_0 + P_2 P_1 P_0 C_0]$$

$$C_{i+4} = G_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0 + P_3 P_2 P_1 P_0 C_0$$

An important point to note is that all of the sum equations and the final carry output equation, C_{i+4} , can be written in terms of the A_i , B_i , and C_0 inputs to the four-bit adder. The configuration as described above is shown in Figure 3. This figure is divided into two parts — the upper blocks show the auxiliary function generator circuitry required to implement the P_i and G_i equations while the lower block implements the logic required to generate the sum output at each bit position.

A serious drawback to the lookahead carry adder is that as the word length is increased, the carry functions become more and more complex, eventually becoming impractical due to the large number of interconnections and heavy loading of the G_i and P_i functions. The auxiliary function concept can be extended, however, by dividing the word length into fairly small increments and defining blocks of auxiliary functions G and P .

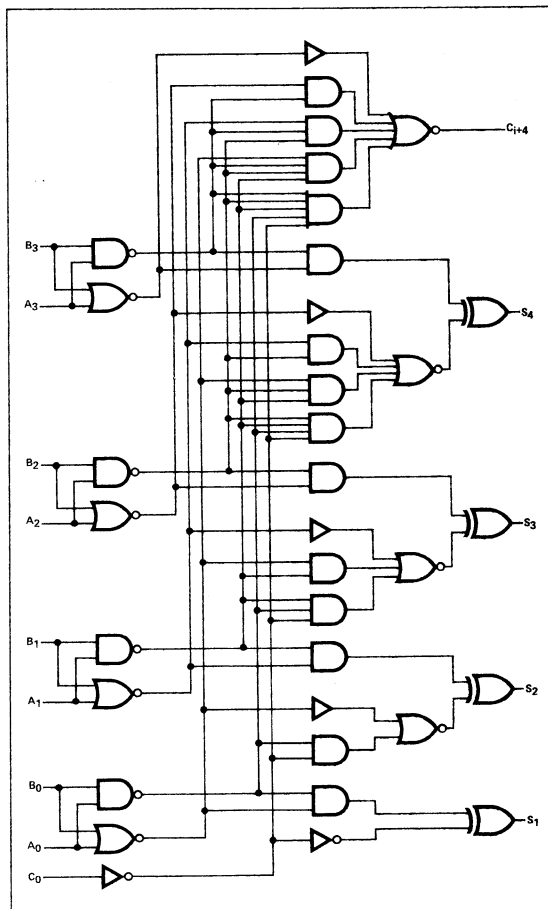


Figure 3. Full Four-Bit Carry-Lookahead Adder.

It is possible for a given block, to define a function G as the carry out generated with the block; and P can be defined as the carry propagate over the block. If the block size is set at four bits, then the functions for G and P for this block can be defined as follows:

$$G = G_3 + P_3 G_2 + P_3 P_2 G_1 + P_3 P_2 P_1 G_0$$

$$P = P_3 P_2 P_1 P_0$$

It is important to note that neither of these terms involves a carry-in (C_0) to the block, so no matter how many blocks are tied in an adder, all the blocks have stable G and P functions available in a minimum number of gate delays.

The G and P functions can be gated to produce a carry-in to each four-bit block, as a function of the lesser significant blocks. The carry-in to a block is therefore:

$$C_n = G_{n-1} + P_{n-1} G_{n-2} + P_{n-1} P_{n-2} G_{n-3} + \dots + P_{n-1} P_{n-2} P_{n-3} \dots P_2 P_1 P_0 C_0$$

Finally, the carry-in to each of the bits in a four-bit block must include a term for the actual least significant carry-in; note, therefore, that the equations for the four-bit full adder presented above include a term for carry-in at each bit position. Figure 4 shows the logic diagram for the Am25LS381 arithmetic logic unit/function generator while Figure 5 shows the logic diagram for the Am25LS2517 arithmetic logic unit/function generator. Note the generate and propagate outputs

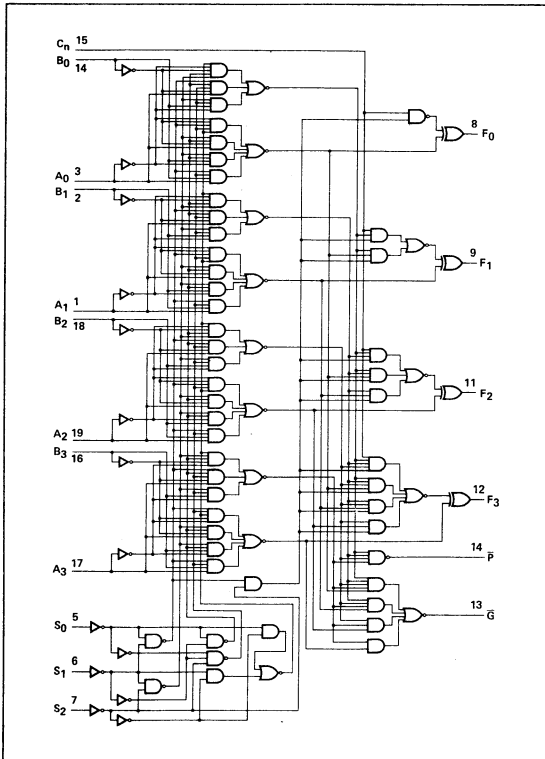


Figure 4. Logic Diagram of The Am25LS381.

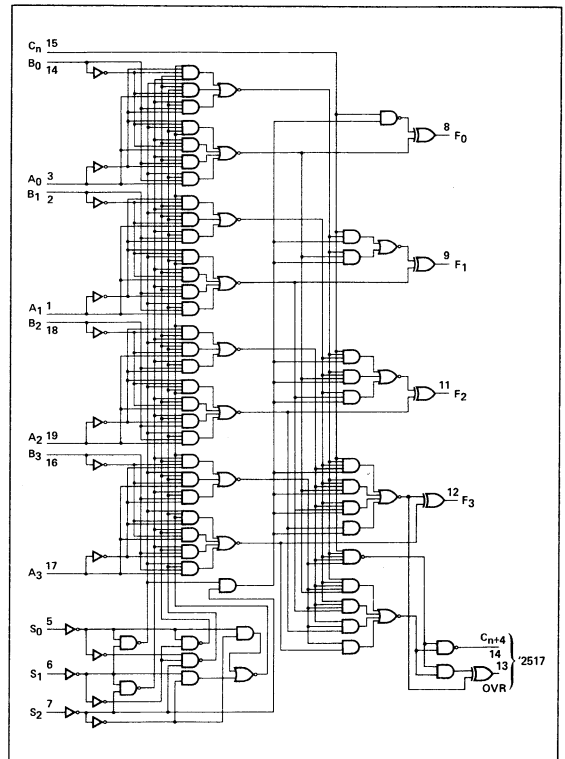


Figure 5. Logic Diagram of the Am25LS2517.

on the Am25LS381, and the carry output and overflow output on the Am25LS2517. Figure 6 gives the function table for both the Am25LS2517 and Am25LS381. Figure 7 shows the technique for cascading three Am25LS381's, one Am25LS2517, and one Am2902 in a full 16-bit high-speed carry lookahead connection. Figure 8 shows a connection scheme using only four Am25LS2517's in a 16-bit arithmetic logic unit connection where the carries are rippled between the devices. Each Am25LS2517 does use internal carry lookahead over the four-bit block.

In summary, the ripple carry method can be used in conjunction with the lookahead technique in several ways.

1. Lookahead carry over sections of the adder and ripple carry between these sections of the adder can be used. This method is often the most efficient in terms of hardware for

Selection			Arithmetic/Logic Operation
S ₂	S ₁	S ₀	
L	L	L	Clear
L	L	H	B Minus A
L	H	L	A Minus B
L	H	H	A Plus B
H	L	L	A ⊗ B
H	L	H	A + B
H	H	L	AB
H	H	H	Preset

H = High Level, L = Low Level

Figure 6. Function Table for the Am25LS2517 and Am25LS381.

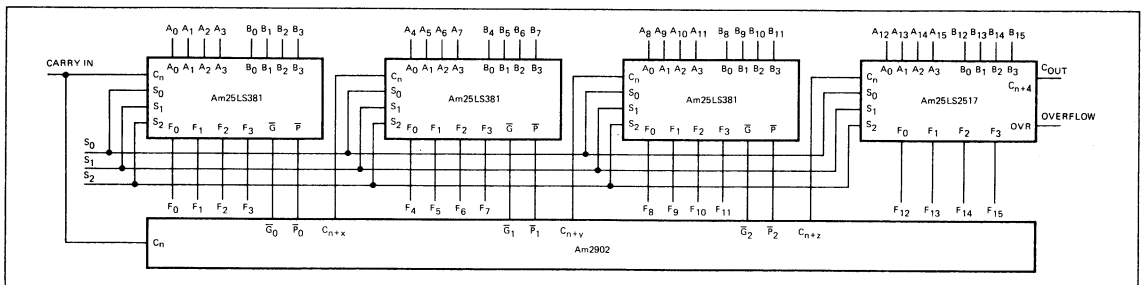


Figure 7. Full Lookahead Carry 16-Bit Adder.

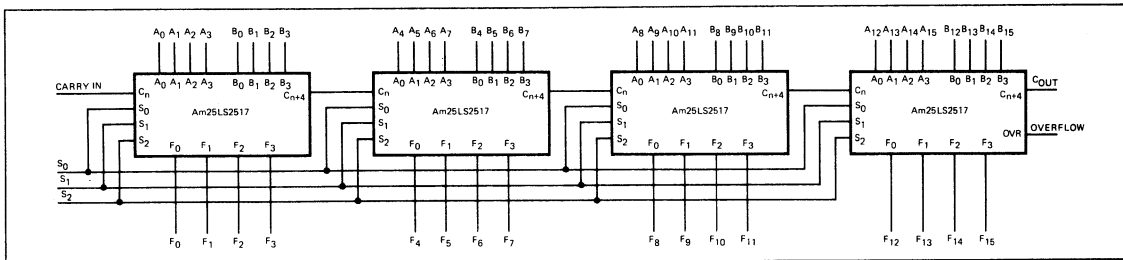


Figure 8. Connection of 16-Bit ALU Using Ripple Carry.

a given speed requirement. It does not require the use of a lookahead carry generator such as the Am2902.

2. Lookahead carry across 16-bit blocks with a ripple carry between 16-bit blocks can be used. This technique is usually called two-level carry lookahead addition. This technique results in very high-speed arithmetic function generation and makes a reasonable tradeoff between the speed and hardware for word lengths greater than 16 bits.
3. Full lookahead carry across all levels and all block sizes can be used. This is the highest speed arithmetic logic unit connection scheme. For word sizes up to 64 bits, it is referred to as three-level lookahead carry addition. Such a 64-bit ALU requires the use of five Am2902 carry lookahead generator units in addition to the 15 Am25LS381 devices and one Am25LS2517 as shown in Figure 9.

position is after the least significant bit. The actual choice for the location of the binary point is really up to the design engineer, as the hardware configuration required for either technique is identical. It is also possible to use number notations that include both integer and fractional representations in the same numbering scheme. Overflow is defined as the situation where the result of an arithmetic operation lies outside of the number range that can be represented by the number of bits in the word. For example, if two eight-bit numbers are added and the result does not lie within the number range that can be represented by an eight-bit word, we say that an overflow has occurred. This can happen at either the positive end of the number range or at the negative end of the number range. The logic function that indicates that the result of an operation is outside of the representable number range is:

$$OVR = C_S \oplus C_{S+1}$$

where C_S is the carry-in to the sign bit and C_{S+1} is the carry-out of the sign bit.

Thus, for a four-bit ALU with the sign bit in the most significant bit position, the overflow can be defined as the C_{n+4} term exclusive OR'ed with the C_{n+3} term.

OVERFLOW

When two's complement numbers are added or subtracted, the result must lie within the range of the numbers that can be handled by the operand word length. Numbers are normally represented either as fractions with a binary point between the sign bit and the rest of the word, or as integers where the binary

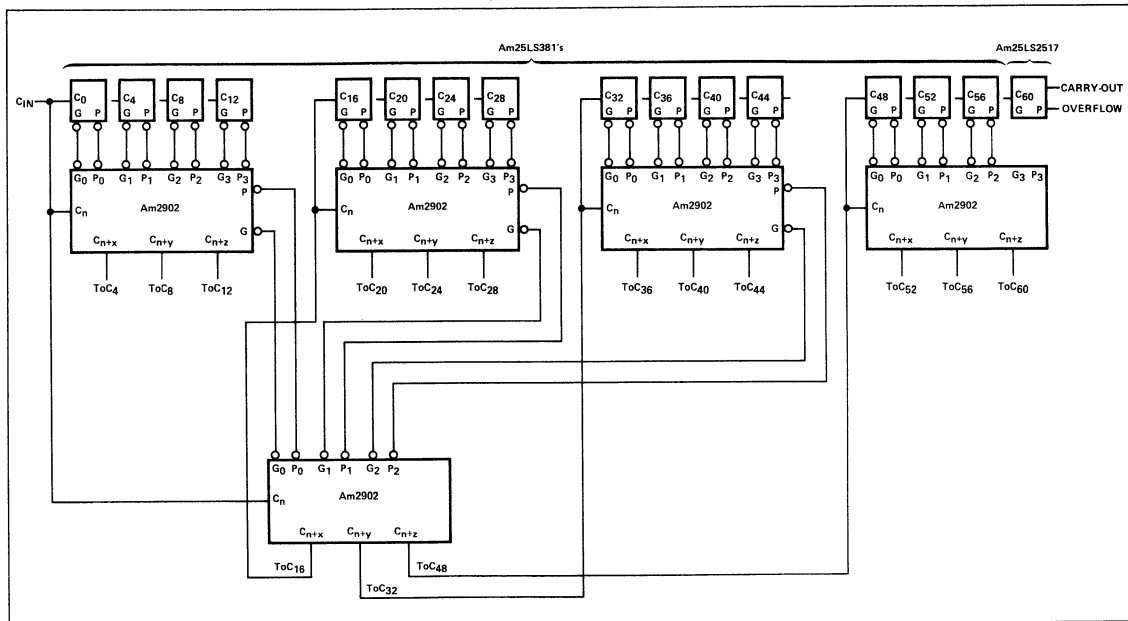


Figure 9. 64-Bit ALU with Full Carry Lookahead Using 5 Am2902's, 15 Am25LS381's and 1 Am25LS2517.

SPEED OR DELAY

Usually, the most important parameter in the design of any arithmetic logic unit is speed. How fast can two numbers be added? Is ripple carry sufficient or should carry lookahead over the entire adder array be used? In order to answer these questions, the design engineer must first evaluate the speed of the ALU required in his system. Then he can evaluate the various alternatives based on the number of bits in the word being used in the design.

The calculation of the speed (add or subtract time) of a 16-bit adder is straightforward and will be discussed in detail. It should be mentioned that the speed of the adder while in the logic mode is simply the propagation delay from the A_i or B_j inputs to the F_i outputs (35ns maximum at 25°C and 5V for the Am25LS2517).

LOOKAHEAD CARRY

The typical method for building 16-bit ALU's is to employ a carry lookahead generator such as the Am2902. Such a 16-bit design would incorporate three Am25LS381's, one Am25LS2517, and one Am2902. For the 16-bit full carry lookahead adder in the add or subtract mode as shown in Figure 7, the maximum propagation delay for data-in to data-out is calculated as follows:

**DATA PATH DELAY
16-BIT LOOKAHEAD ADDER/SUBTRACTOR
(+5V and 25°C Maximum Delays)**

Path	Output			Units
	F_i	C_{n+4}	OVR	
A_i or B_j to \bar{G} or \bar{P}	27	27	27	ns
G_i or P_j to C_{i+j} (Am2902)	10	10	10	ns
C_n to F_i	23	—	—	ns
C_n to C_{n+4} or OVR	—	22	22	ns
TOTAL				
16-bit delay	60	59	59	ns

The data path for this computation begins at the least significant 4-bit device, propagates through the Am2902, and then ends at the most significant 4-bit device. Actually, the delay to the outputs of the most significant device (MSD), then second MSD, or third MSD is identical.

Thus, the above speed is identical if a 12-bit ALU is fabricated. This results because the same types of combinatorial propagation delays are involved.

We should also investigate the delay of this adder with regard to the select inputs as shown in Figure 7. Again, we may calculate the 16-bit full carry lookahead add/subtract delay as follows:

**16-BIT LOOKAHEAD ADDER DELAY
FOR SELECT INPUTS
(+5V and 25°C Maximum Delays)**

Path	Output			Units
	F_i	C_{n+4}	OVR	
S_i to \bar{G} or \bar{P}	48	48	48	ns
G_i or P_j to C_{i+j} (Am2902)	10	10	10	ns
C_n to F_i	23	—	—	ns
C_n to C_{n+4} or OVR	—	22	22	ns
TOTAL				
16-bit delay	81	80	80	ns

Let us examine the speed of a 64-bit arithmetic logic unit fabricated as shown in Figure 9. The worst case path for this design is as follows:

**DATA PATH DELAY
64-BIT LOOKAHEAD ADDER/SUBTRACTOR
(+5V and 25°C Maximum Delays)**

Path	Output			Units
	F_i	C_{n+4}	OVR	
A_i or B_j to \bar{G} or \bar{P}	27	27	27	ns
G_i or P_j to G_i or P_j (Am2902)	14	14	14	ns
G_i or P_j to C_{i+j} (Am2902)	10	10	10	ns
C_n to C_{i+j} (Am2902)	14	14	14	ns
C_n to F_i	23	—	—	ns
C_n to C_{n+4} or OVR	—	22	22	ns
TOTAL				
16-bit delay	88	87	87	ns

The above example demonstrates the speed improvement when using carry lookahead over the entire array. When this 64-bit example is compared with the previous 16-bit example, it will be found that the only difference is the addition of two Am2902 delays.

RIPPLE CARRY

The slowest speed ALU design employs the ripple carry technique. When four-bit devices such as the Am25LS2517 are employed in such an ALU, the speed is usually computed using the combinatorial delay terms in the following manner.

1. Select the longest combinatorial delay in the least significant device from any input to the carry output, C_{n+4} . This is usually from the A or B inputs to the carry output.
2. Add the carry input to carry output propagation delay as many times as required to represent each of the intermediate four-bit ALU's.
3. Finally, take the propagation delay from the carry input to the ALU adder outputs.

When the above rules are followed, the total worst case propagation delay over the entire ALU bit width is derived.

If we consider the ripple carry adder/subtractor configuration as shown in Figure 8, the propagation delay for the data input to data output path is computed as follows:

**DATA PATH DELAY
64-BIT RIPPLE CARRY ADDER/SUBTRACTOR
(+5V and +25°C Maximum Delays)**

Path	Output			Units
	F_i	C_{n+4}	OVR	
A_i or B_j to C_{n+4}	36	36	36	ns
C_n to C_{n+4}	22	22	22	ns
C_n to C_{n+4}	22	22	22	ns
C_n to F_i	23	—	—	ns
C_n to C_{n+4} or OVR	—	22	22	ns
TOTAL				
16-bit delay	103	102	102	ns

In this connection, the maximum delay begins at the least significant device and propagates through the most significant device via the ripple carry path.

The select to output delay is computed in a similar manner using S_i to C_{n+4} as the first term and is found to be:

S_i to $F_i = 122ns$; S_i to $C_{n+4} = 12ns$; S_i to OVR = 121ns

The ripple carry computational examples show the speed of a 16-bit ALU function/generator built using four Am25LS 2517's.

COMPARING THE '2517/'381 WITH THE '181

To compare the performance of the Am25LS2517 and LS381, we should evaluate the various '181 ALU's connected in a 16-bit configuration with the Am2902 carry lookahead generator used in all configurations as shown in Figure 7. The comparison for the A_i or B_i to F_i add/subtract time is as follows:

COMPARISON OF 16-BIT ADDER/SUBTRACTOR DATA DELAY USING 4 ALU's AND 1 Am2902

ALU Device	Maximum Add/Subtract Delay +5V and 25°C	Maximum Power* VCC = +5.25V
Am74S181	37ns	914mA
Am74181	64ns	694mA
Am74LS181	69ns	242mA
Am25LS181	55ns	242mA
Am25LS381/Am25LS2517	60ns	266mA

*Note: Of this power, 94mA is the Am2902

Even more important is the comparison of "System Speed" normally associated with the ALU function. If we assume the system configuration as shown in Figure 10, then a reasonable comparison of speed for A_i or B_i to OVERFLOW can be made as follows:

SPEED AND POWER FOR ALU SYSTEMS OF FIGURE 10

Path	All "S"	All 25LS	All 74LS	All Gold Doped	'LS381 'LS2517	Units
A_i or B_i to \overline{G} or \overline{P}	15	26	33	25	27	ns
\overline{G} or \overline{P} to C_{i+j} (Am2902)	10	10	10	10	10	ns
C_n to OVR	—	—	—	—	22	ns
C_n to F_3	12	19	26	19	—	ns
Inverter	5	20*	20	22	—	ns
MUX to OVR ('151)	12	24	32	27	—	ns
TOTAL	54	99	121	103	59	ns
POWER	993	253	253	748	266	mA

*no 25LS

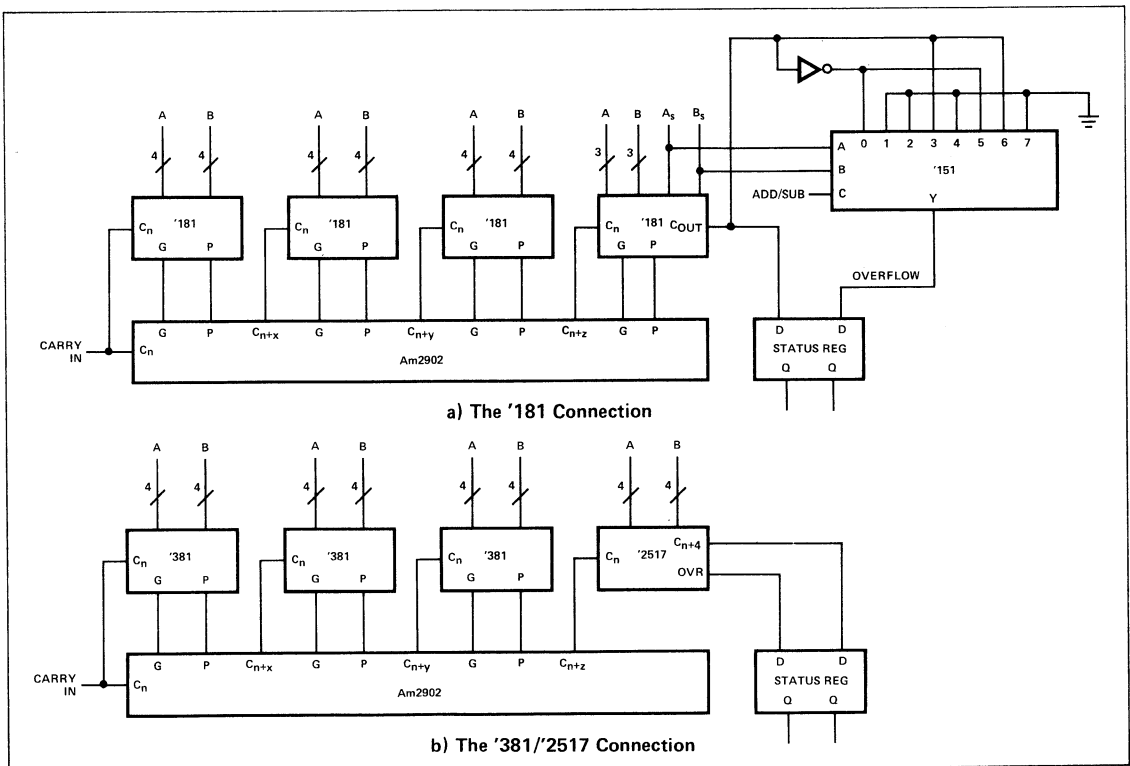


Figure 10. The Normal ALU System.

SUMMARY

The Am25LS381 and Am25LS2517 offer superior performance utilizing the space saving 20-pin package. The data add/subtract time compares very favorably with the 74181 and 74S181 with a considerable reduction (1/3 to 1/4) in dissi-

pated power. The Am25LS381 and Am25LS2517 combination provide the OVR function not currently available or easily to implement on any '181 configuration. The 20-pin package configuration offers at least a 2:1 saving in PC board area compared to the '181 24-pin package approach.

3

Am25LS384 • Am54LS/74LS384

8-Bit Serial/Parallel Two's Complement Multiplier

The 'LS384 is Texas Instruments' planned second source to Advanced Micro Devices' Am25LS14. See Am25LS14 data sheet for full information.

FUNCTIONAL DESCRIPTION

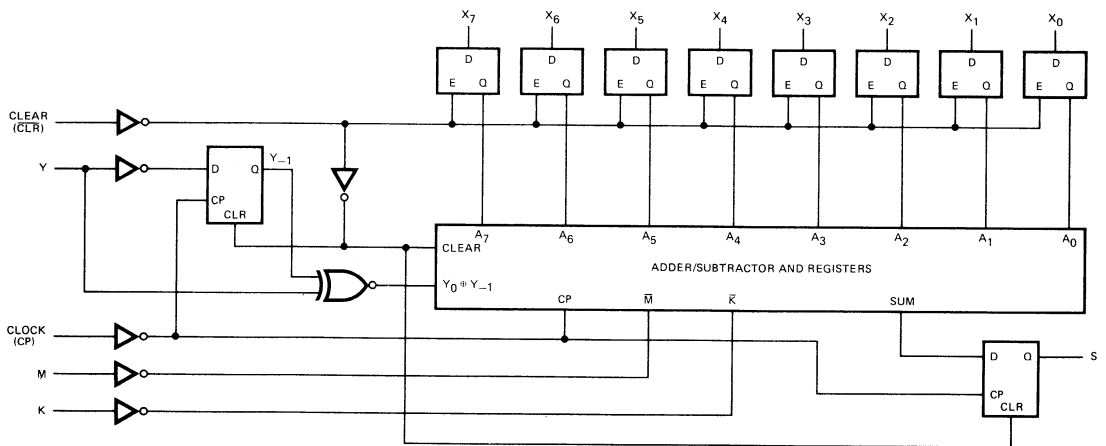
The Am25LS14 is an 8-bit by 1-bit sequential logic element that performs digital multiplication of two numbers represented in two's complement form to produce a two's complement product without correction by using Booth's algorithm internally. The device accepts an 8-bit multiplicand (X input) and stores this data in eight internal latches. The X latches are controlled via the clear input. When the clear input is LOW, all internal flip-flops are cleared and the X latches are opened to accept new multiplicand data. When the clear input is HIGH, the latches are closed and are insensitive to X input changes.

The multiplier word data is passed by the Y input in a serial bit stream — least significant bit first. The product is clocked out the S output least significant bit first.

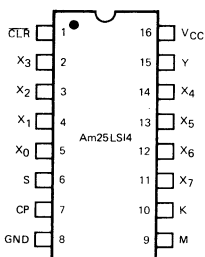
The multiplication of an m-bit multiplicand by an n-bit multiplier results in an m + n bit product. The Am25LS14 must be clocked for m + n clock cycles to produce this two's complement product. Likewise, the n-bit multiplier (Y-input) sign bit data must be extended for the remaining m-bits to complete the multiplication cycle.

The device also contains a K input so that devices can be cascaded for longer length X words. The sum (S) output of one device is connected to the K input of the succeeding device when cascading. Likewise, a mode input (M) is used to indicate which device contains the most significant bit. The mode input is wired HIGH or LOW depending on the position of the 8-bit slice in the total X word length.

LOGIC DIAGRAM

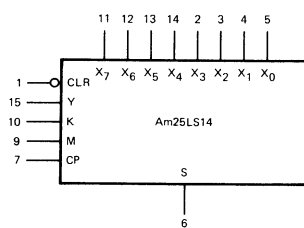


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

Am25LS385 • Am54LS/74LS385

Quad Serial Adder/Subtractor

'LS385 is Texas Instruments' planned second source to Advanced Micro Devices' Am25LS15.

See Am25LS15 data sheet for full information.

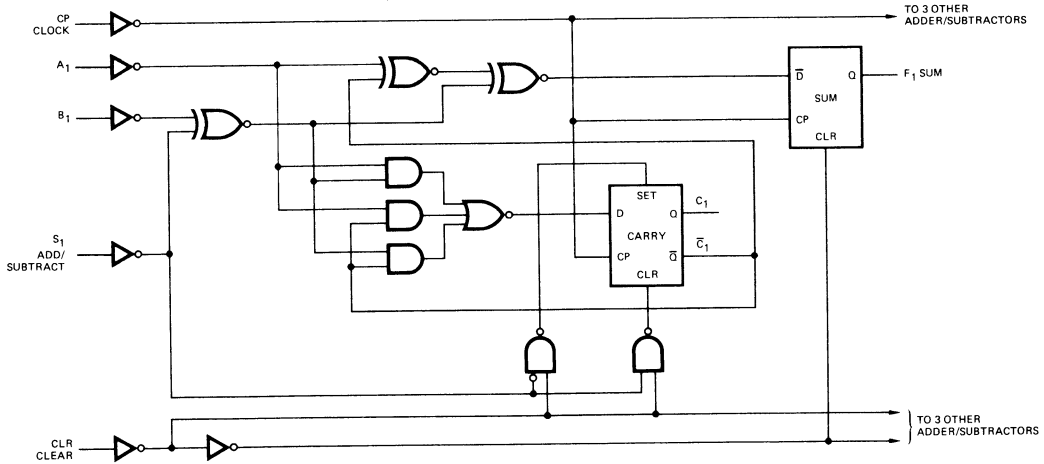
FUNCTIONAL DESCRIPTION

The Am25LS15 is a serial two's complement adder/subtractor designed for use in association with the Am25LS14 serial/parallel two's complement multiplier. This device can also be used for magnitude only or one's complement addition or subtraction.

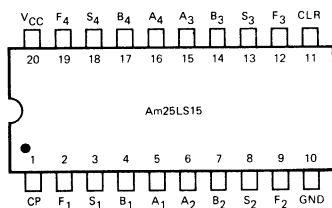
Four independent adder/subtractors are provided with common clock and clear inputs. The add function is A plus B and the subtract function is A minus B. The clear function sets the internal carry function to logic zero in the add mode and to logic one in subtract mode. This least significant carry is self propagating in the subtract mode as long as zeroes are applied to the A and B inputs at the LSB's. All internal flip-flops change state on the LOW-to-HIGH clock transition.

The Am25LS15 is particularly useful for recursive or non-recursive digital filtering or butterfly networks in Fast Fourier Transforms.

LOGIC DIAGRAM (One of Four Similar Functions)

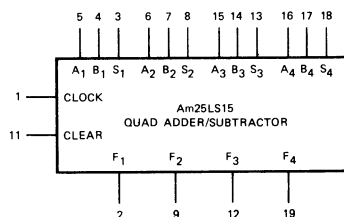


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 20
GND = Pin 10

Am25LS388 • Am54LS/74LS388

Quad D Register with Standard and Three-State Outputs

The 'LS388 is Texas Instruments' planned second source to Advanced Micro Devices Am25LS2518.

See Am25LS2518 data sheet for full information.

FUNCTIONAL DESCRIPTION

The Am25LS2518 consists of four D-type flip-flops with a buffered common clock. Information meeting the set-up and hold requirements on the D inputs is transferred to the Q outputs on the LOW-to-HIGH transition of the clock.

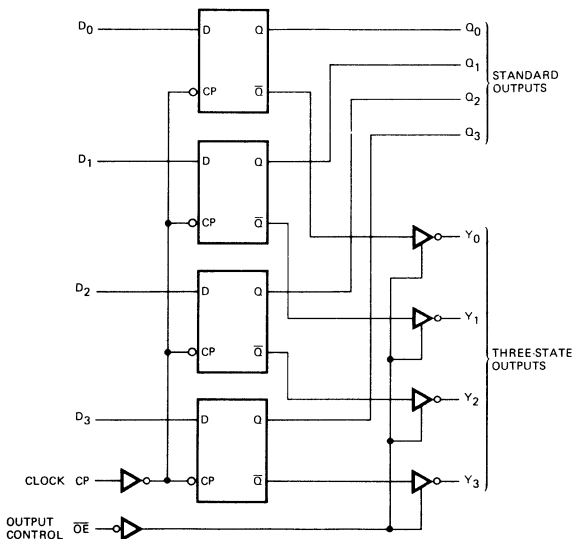
The same data as on the Q outputs is enabled at the three-state Y outputs when the "output control" (\overline{OE}) input is LOW. When the \overline{OE} input is HIGH, the Y outputs are in the high-impedance state.

The Am25LS2518 is a 4-bit, high-speed register intended for use in real-time signal processing systems where the standard outputs are used in a recursive algorithm and the three-state outputs provide access to a data bus to dump the results after a number of iterations.

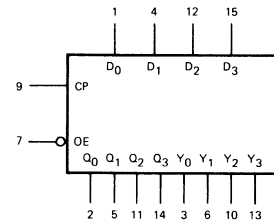
The device can also be used as an address register or status register in computers or computer peripherals.

Likewise, the Am25LS2518 is also useful in certain display applications where the standard outputs can be decoded to drive LED's (or equivalent) and the three-state outputs are bus organized for occasional interrogation of the data as displayed.

LOGIC DIAGRAM

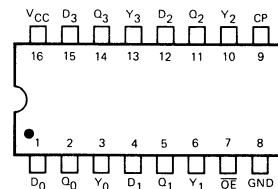


LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

Am25LS399 • Am54LS/74LS399

Quad Two-Input Register

DISTINCTIVE CHARACTERISTICS

- Four-bit register accepts data from one of two 4-bit input fields
- Positive, edge-triggered clock
- Am25LS devices offer the following improvements over Am54/74LS
 - Higher speed
 - 50mV lower V_{OL} at $I_{OL} = 8\text{mA}$
 - Twice the fan-out over military range
 - 440 μA source current at HIGH output
- 100% product assurance screening to MIL-STD-883 requirements

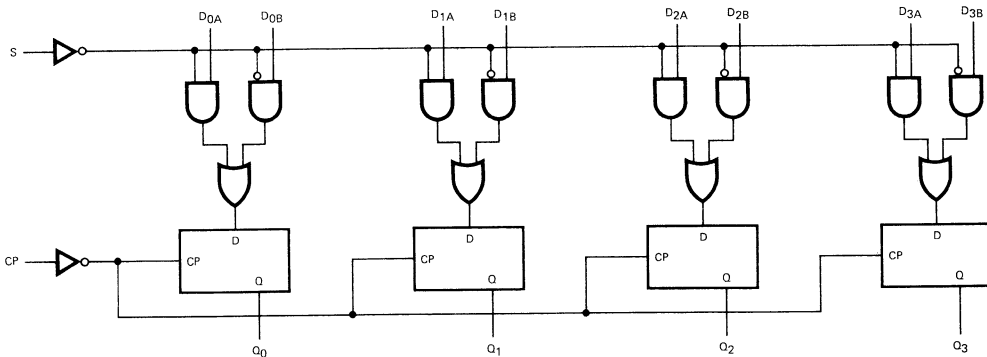
FUNCTIONAL DESCRIPTION

The Am25LS399 and Am54LS/74LS399 are dual input port, four-bit registers built using advanced Low-Power Schottky processing. The registers consist of four D-type flip-flops with a buffered common clock. Each flip-flop has a two-input multiplexer at its data input such that it can be loaded with incoming data from one of two sources. A buffered common select line, S, controls the four 2-input multiplexers.

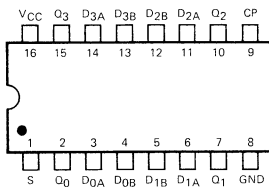
Data on the four inputs selected by the S line is stored in the four flip-flops on the LOW-to-HIGH transition of the clock. When the S input is LOW, the D_{1A} input data will be stored in the register. When the S input is HIGH, the D_{1B} input data will be stored in the register.

The Am54LS/74LS399 is a standard performance version of the Am25LS399. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAM

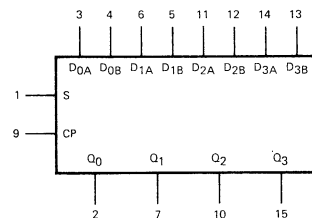


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

Am25LS399

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 VMIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -440\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4	Volts
			COM'L	2.7	3.4	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.},$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.4	Volts
			$I_{OL} = 8.0\text{mA}$		0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$	Clock		-0.36	mA
			Others		-0.24	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$	Clock		20	μA
			Others		14	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		11	18	mA

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. Measured with select and clock inputs at 4.5 V, all data inputs at 0 V, all outputs open.

Am25LS • Am54LS/74LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am54LS/74LS399

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{ V} \pm 5\%$	MIN. = 4.75 V	MAX. = 5.25 V
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{ V} \pm 10\%$	MIN. = 4.50 V	MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -400\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	All, $I_{OL} = 4.0\text{mA}$		0.4		Volts
			74LS only, $I_{OL} = 8.0\text{mA}$		0.5		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7		Volts
			COM'L		0.8		
V_i	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.4	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-100	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		11	18	mA	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Measured with select and clock inputs at 4.5 V, all data inputs at 0 V, all outputs open.

FUNCTION TABLE

SELECT S	CLOCK CP	DATA D_{iA}	INPUTS D_{iB}	OUTPUT Q_i
L	↑	L	X	L
L	↑	H	X	H
H	↑	X	L	L
H	↑	X	H	H

H = HIGH Voltage Level
 X = Don't Care
 ↑ = LOW-to-HIGH Transition

L = LOW Voltage Level
 i = 0, 1, 2, or 3

DEFINITION OF FUNCTIONAL TERMS

$D_{0A}, D_{1A}, D_{2A}, D_{3A}$ The "A" word into the two-input multiplexer of the D flip-flops.

$D_{0B}, D_{1B}, D_{2B}, D_{3B}$ The "B" word into the two-input multiplexer of the D flip-flops.

Q_0, Q_1, Q_2, Q_3 The outputs of the four D-type flip-flops of the register.

S Select. When the select is LOW, the A word is applied to the D inputs of the flip-flops. When the select is HIGH the B word is applied to the D inputs of the flip-flops.

CP Clock Pulse. Clock pulse for the register. Enters data on the LOW-to-HIGH transition of the clock line.

Am25LS/54LS/74LS399

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Am25LS			Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.	Min.	Typ.	Max.		
t_{PLH}	Clock to Output		13	20		18	27	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			13	20		21	32		
tpW	Clock Pulse Width	17			20		ns		
t_s	Data	20			20		ns		
t_h	Data	5.0			5.0		ns		
t_s	Select	30			30		ns		
t_h	Select	0			0		ns		
f_{max}	Maximum Clock Frequency (Note 1)	40	65		30	40	MHz		

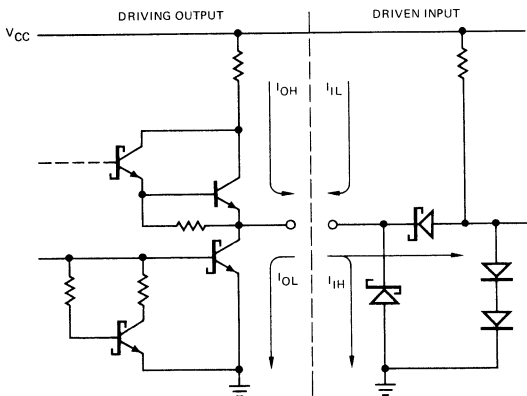
Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

Am25LS ONLY SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions	
		Min.	Max.	Min.	Max.			
t_{PLH}	Clock to Output	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$		ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$	
t_{PHL}			30		35			
tpW	Clock Pulse Width	26		30	35			ns
t_s	Data	30		35				ns
t_h	Data	11		12				ns
t_s	Select	43		50				ns
t_h	Select	4		5				ns
f_{max}	Maximum Clock Frequency (Note 1)	30		26				MHz

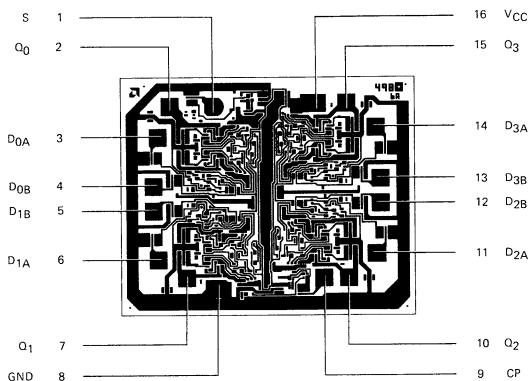
*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

**Am25LS Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**



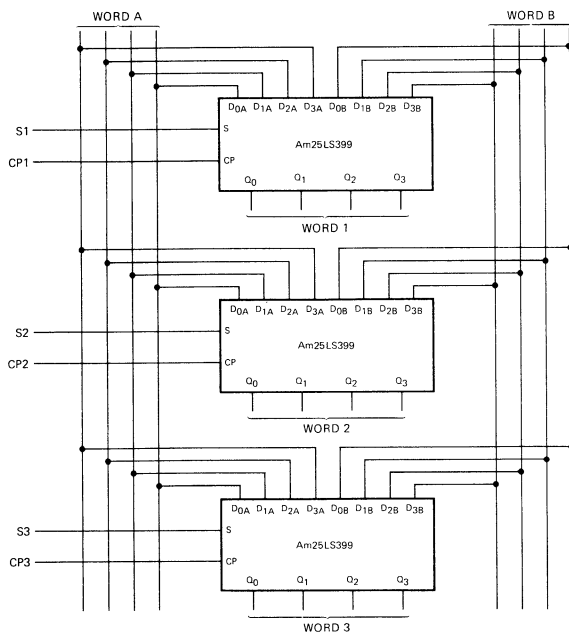
Note: Actual current flow direction shown.

Metallization and Pad Layout



DIE SIZE 0.075" X 0.061"

APPLICATION



Am25LS399 used to store a word from either data bus A or data bus B.

Am54LS/74LS424

Clock Generator and Driver for 8080A Compatible Microprocessors

The SN54LS/74LS424 is Texas Instruments second source part number to the AMD/Intel 8224 device.

See the current issue of the Am8224 data sheet for full information.

Am54LS/74LS568 • Am54LS/74LS569

Four-Bit Up/Down Counters with Three State Outputs

The 54LS/74LS568 and 54LS/74LS569 are other manufacturers alternate source part numbers to the Advanced Micro Devices' Am25LS2568 and Am25LS2569.

See the Am25LS2568 and Am25LS2569 data sheets for full information.

Am54LS/74LS668 • Am54LS/74LS669

Synchronous Up/Down Decade and Binary Counters

The SN54LS/74LS668 and SN54LS/74LS669 are reduced speed versions of the 54LS/74LS168A and 54LS/74LS169A.

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25V
MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

DC Characteristics are the same as the 54LS/74LS168A and 54LS/74LS169A devices.

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Am54LS/74LS			Units	Test Conditions
		Min.	Typ.	Max.		
t_{PLH}	Clock to Ripple Carry		26	40	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			40	60		
t_{PLH}	Clock to any Q		18	27	ns	
t_{PHL}			18	27		
t_{PLH}	Enable \bar{T} to Ripple Carry		11	17	ns	
t_{PHL}			29	45		
t_{PLH}	Up/Down to Ripple Carry		22	35	ns	
t_{PHL}			26	40		
t_{pw}	Clock Pulse Width	25			ns	
t_s	Set-up	A, B, C, D	20		ns	
		\bar{EN} , P, \bar{EN} , \bar{T}	20			
		Load	25		ns	
		Up/Down	30			
t_h	Hold, any Input	0			ns	
f_{max} (Note 1)	Maximum Clock Frequency	25			MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

Three-state output, 20-pin versions are also available as the Am25LS2568 and Am25LS2569.

Am25LS670 • Am54LS/74LS670

4-By-4 Register File with 3-State or Open Collector Outputs

Am25LS670 • Am54LS/74LS670 data is combined with the Am25LS170.

See Am25LS170 data sheet for full information.

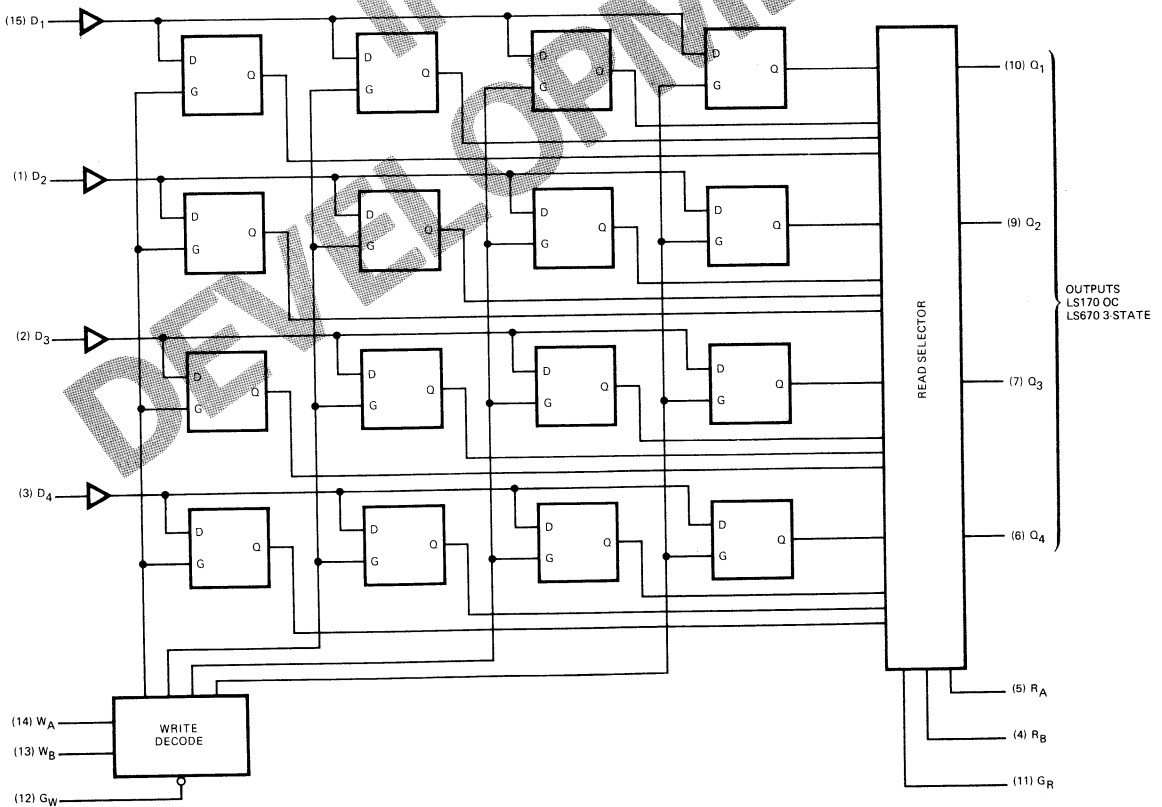
FUNCTIONAL DESCRIPTION

The Am25LS170 and 670 are 16-bit low-power Schottky register files. The file is organized as 4 words of 4-bits each with separate on-chip address decoding for read and write. This permits simultaneous read and write operations either to the same or different addresses.

Four data inputs are used to supply the 4-bit data word to be stored. The W_A and W_B inputs supply the write address while the G_W supplies the write enable. Four data outputs (O_0 to O_3) are selected from data word cells by the R_A and R_B address. The output is available if the read enable G_R is LOW. The register file performs a non-destructive readout. The Am25LS170 has open collector output for convenience of collector ORing while the Am25LS670 provides three-state outputs for bus selection.

The Am54LS/74LS170 and 670 are standard performance versions of the Am25LS160 and 670. See appropriate electrical characteristic tables for detailed Am25LS improvements.

LOGIC DIAGRAM



Am25LS2513

Three-State Priority Encoder

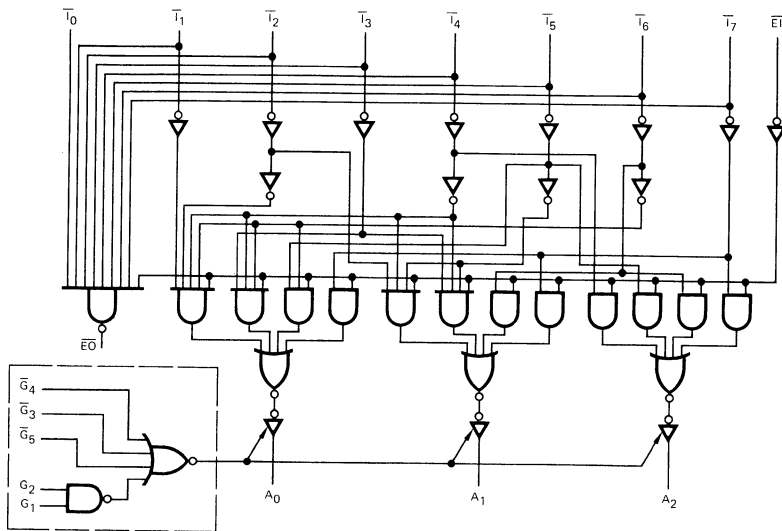
DISTINCTIVE CHARACTERISTICS

- Encodes eight lines to three-line binary
- Expandable
- Cascadable
- Three State inverted output version of Am54LS/74LS/25LS148
- Gated three-state output
- Advanced Low-Power Schottky processing
- 100% product assurance screening to MIL-STD-883 requirements

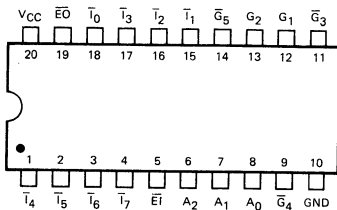
FUNCTIONAL DESCRIPTION

The Am25LS2513 Low-Power Schottky Priority Encoder performs priority encoding of 8 inputs to provide a binary-weighted code of the priority order of the 3 tri-state active HIGH outputs A_0 , A_1 , A_2 . Three active LOW and two active HIGH inputs in AND-OR configuration allow control of the tri-state outputs. The use of the input enable ($\bar{E}I$) combined with the enable output ($\bar{E}O$) permits cascading without additional circuitry. Enable input ($\bar{E}I$) HIGH will force all outputs LOW subject to the tri-state control. The enable output is LOW when all inputs I_0 through I_7 are HIGH and the enable input is LOW.

LOGIC DIAGRAM

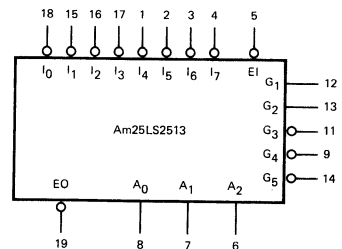


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



Am25LS2513

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 V
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL, $I_{OH} = -1.0\text{mA}$	2.4	3.4	Volts	
			COM'L, $I_{OH} = -2.6\text{mA}$	2.4	3.2		
			$\overline{E}O$, $I_{OH} = -440\mu\text{A}$	MIL	2.5		3.4
				COM'L	2.7		3.4
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.4	Volts	
			$I_{OL} = 8.0\text{mA}$		0.45		
			$I_{OL} = 12\text{mA}$ (A_n Outputs)		0.5		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$ $V_{IN} = 0.4\text{V}$	$\overline{E}1, G1, G2, \overline{G}3, \overline{G}4, \overline{G}5, \overline{I}0$		0.4	mA	
			All others		0.8		
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}$ $V_{IN} = 2.7\text{V}$	$\overline{E}1, G1, G2, \overline{G}3, \overline{G}4, \overline{G}5, \overline{I}0$		20	μA	
			All others		40		
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$ $V_{IN} = 7.0\text{V}$	$\overline{E}1, G1, G2, \overline{G}3, \overline{G}4, \overline{G}5, \overline{I}0$		0.1	mA	
			All others		0.2		
I_O	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$		-20	μA	
			$V_O = 2.4\text{V}$		20		
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		15	24	mA	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. All inputs and outputs open.

Am25LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

SWITCHING CHARACTERISTICS

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t _{PLH}	\bar{I}_i to A _n (In-phase)		17	25	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			17	25		
t _{PLH}	\bar{I}_i to A _n (Out-phase)		11	17	ns	
t _{PHL}			12	18		
t _{PLH}	\bar{I}_i to $\bar{E}O$		7.0	11	ns	
t _{PHL}			24	36		
t _{PLH}	$\bar{E}I$ to $\bar{E}O$		11	17	ns	
t _{PHL}			23	34		
t _{PLH}	$\bar{E}I$ to A _n		12	18	ns	
t _{PHL}			14	21		
t _{ZH}	G ₁ or G ₂ to A _n		23	40	ns	
t _{ZL}			20	37		
t _{ZH}	$\bar{G}_3, \bar{G}_4, \bar{G}_5$ to A _n		20	30	ns	
t _{ZL}			18	27		
t _{HZ}	G ₁ or G ₂ to A _n		17	27	ns	C _L = 5.0pF R _L = 2.0kΩ
t _{LZ}			19	28		
t _{HZ}	$\bar{G}_3, \bar{G}_4, \bar{G}_5$ to A _n		16	24	ns	
t _{LZ}			18	27		

SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		T _A = 0°C to +70°C V _{CC} = 5.0V ±5%		T _A = -55°C to +125°C V _{CC} = 5.0V ±10%			
		Min.	Max.	Min.	Max.		
t _{PLH}	\bar{I}_i to A _n (In-phase)		31		37	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			30		34		
t _{PLH}	\bar{I}_i to A _n (Out-phase)		22		27	ns	
t _{PHL}			22		25		
t _{PLH}	\bar{I}_i to $\bar{E}O$		15		18	ns	
t _{PHL}			48		60		
t _{PLH}	$\bar{E}I$ to $\bar{E}O$		19		21	ns	
t _{PHL}			46		57		
t _{PLH}	$\bar{E}I$ to A _n		22		25	ns	
t _{PHL}			27		32		
t _{ZH}	G ₁ or G ₂ to A _n		42		49	ns	
t _{ZL}			43		49		
t _{ZH}	$\bar{G}_3, \bar{G}_4, \bar{G}_5$ to A _n		36		43	ns	
t _{ZL}			35		43		
t _{HZ}	G ₁ or G ₂ to A _n		34		40	ns	C _L = 5.0pF R _L = 2.0kΩ
t _{LZ}			34		40		
t _{HZ}	$\bar{G}_3, \bar{G}_4, \bar{G}_5$ to A _n		30		35	ns	
t _{LZ}			31		35		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

Note: i = 0 to 7
n = 0 to 2

DEFINITIONS OF FUNCTIONAL TERMS

- A0, A1, A2** Three-state, active high encoder outputs
- E \bar{I}** Enable input provided to allow cascaded operation
- E \bar{O}** Enable output provided to enable the next lower order priority chip
- G $_1$, G $_2$** Active high three-state output controls
- $\bar{G}_3, \bar{G}_4, \bar{G}_5$** Active low three-state output controls
- \bar{I}_0-7** Active low encoder inputs

TRUTH TABLE

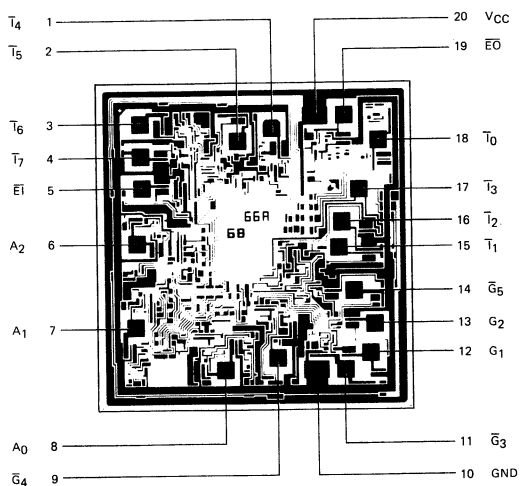
Inputs								Outputs				
E \bar{I}	\bar{I}_0	\bar{I}_1	\bar{I}_2	\bar{I}_3	\bar{I}_4	\bar{I}_5	\bar{I}_6	\bar{I}_7	A $_0$	A $_1$	A $_2$	E \bar{O}
H	X	X	X	X	X	X	X	X	L	L	L	H
L	H	H	H	H	H	H	H	L	L	L	L	L
L	X	X	X	X	X	X	L	H	H	H	H	H
L	X	X	X	X	X	L	H	H	L	H	H	H
L	X	X	X	X	L	H	H	H	L	L	H	H
L	X	X	X	L	H	H	H	H	H	H	L	H
L	X	X	L	H	H	H	H	H	L	L	H	H
L	X	L	H	H	H	H	H	H	H	L	L	H
L	L	H	H	H	H	H	H	L	L	L	H	H

H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Don't Care
 For G $_1$ = H, G $_2$ = H, G $_3$ = L, G $_4$ = L, G $_5$ = L

G $_1$	G $_2$	\bar{G}_3	\bar{G}_4	\bar{G}_5	A $_0$	A $_1$	A $_2$
H	H	L	L	L	Enabled	Z	Z
L	X	X	X	X	Z	Z	Z
X	L	X	X	X	Z	Z	Z
X	X	H	X	X	Z	Z	Z
X	X	X	H	X	Z	Z	Z
X	X	X	X	H	Z	Z	Z

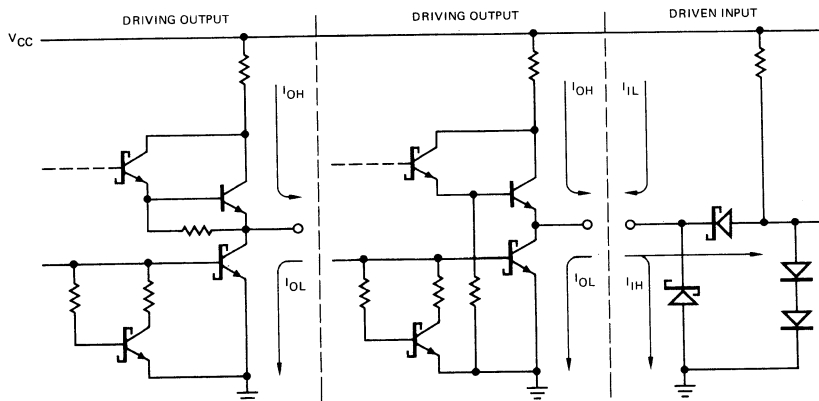
Z = HIGH Impedance

Metallization and Pad Layout



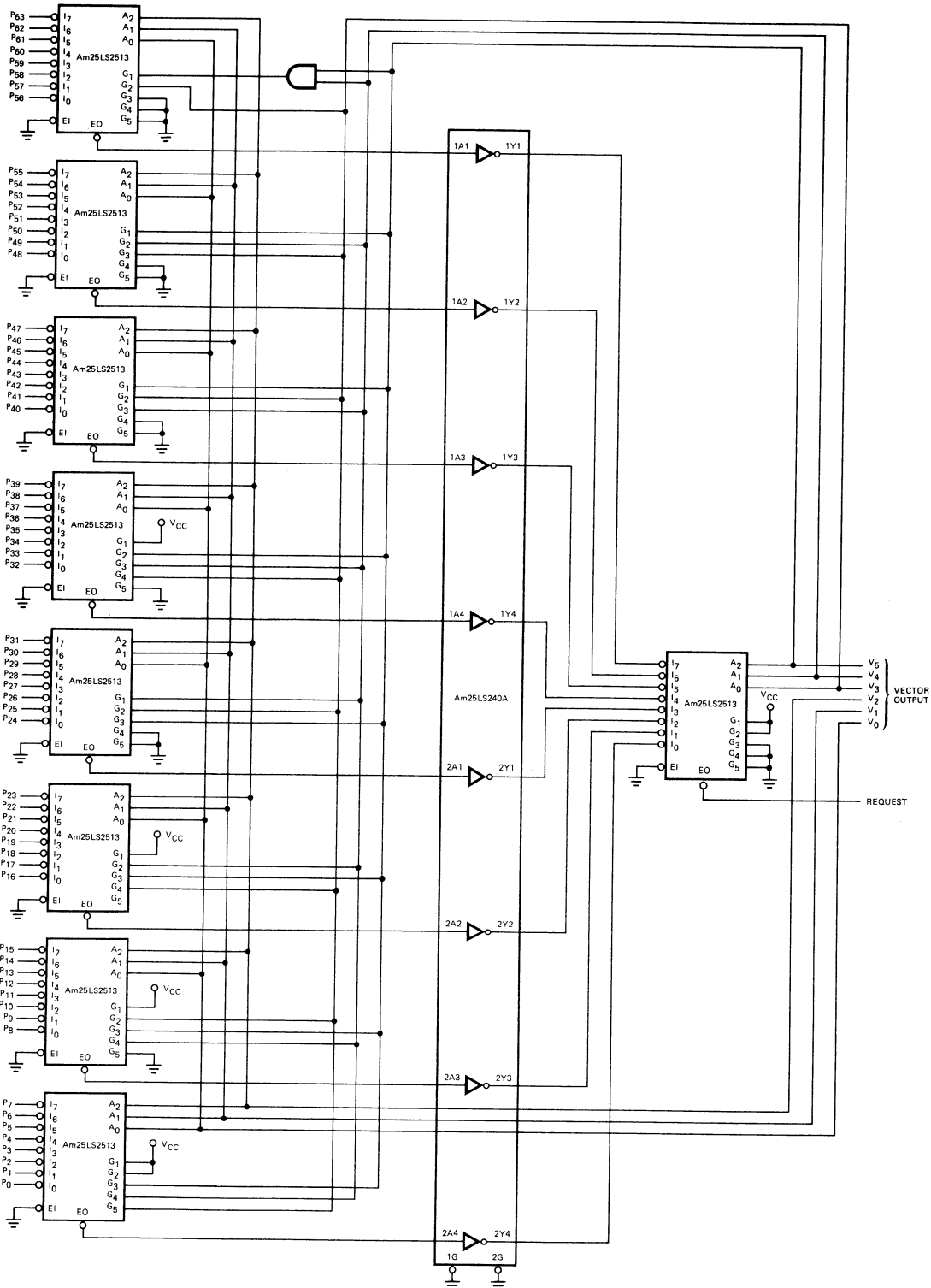
DIE SIZE 0.082 X 0.085

Am25LS LOW-POWER SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

APPLICATION

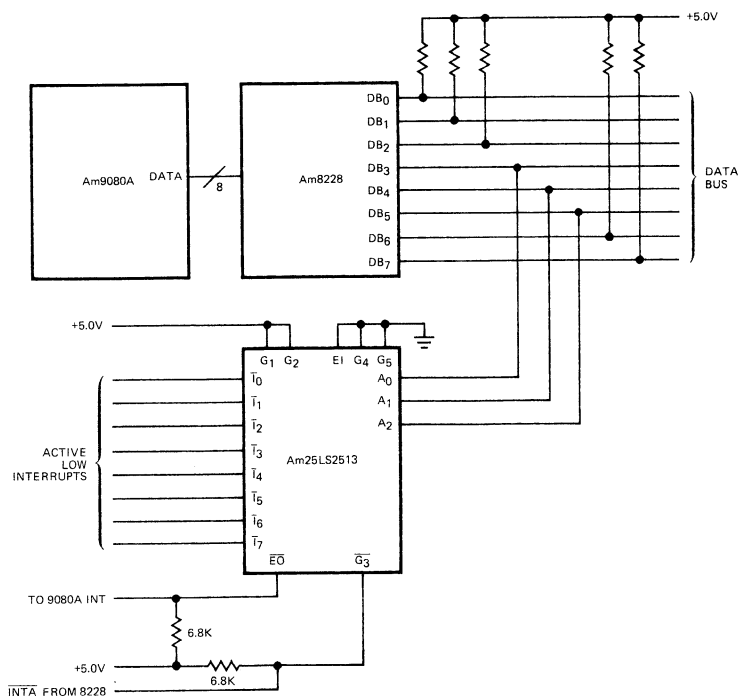


64 Input Priority Encoder Connected for Parallel Enable

ORDERING INFORMATION

Package Type	Temperature Range	Am25LS2513 Order Number
Molded DIP	0°C to +70°C	AM25LS2513PC
Hermetic DIP	0°C to +70°C	AM25LS2513DC
Dice	0°C to +70°C	AM25LS2513XC
Hermetic DIP	-55°C to +125°C	AM25LS2513DM
Hermetic Flat Pak	-55°C to +125°C	AM25LS2513FM
Dice	-55°C to +125°C	AM25LS2513XM

PRIORITY ENCODED RST INTERRUPT
INSTRUCTION FOR THE Am9080A



3

Am25LS2516

Eight-Bit By Eight-Bit Serial/Parallel Multiplier with Accumulator

DISTINCTIVE CHARACTERISTICS

- Two's complement, two-bit lookahead carry-save arithmetic
- Microprogrammable — four-bit instruction code for load, multiply, and read operations
- Cascadable, two devices perform full 16-bit multiplication without additional hardware
- Eight-bit byte parallel, bidirectional, bussed I/O
- On-chip registers and double length accumulator
- Overflow indicator
- Three-state shared bus input/output lines
- High-speed architecture provides clock rates of 20MHz (Typ)
- 100% product assurance screening to MIL-STD-883 requirements

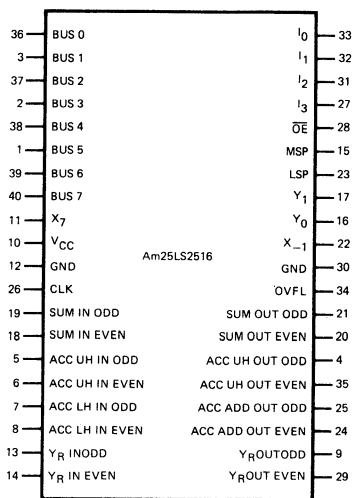
FUNCTIONAL DESCRIPTION

The Am25LS2516 is an eight-bit by eight-bit multiplier and accumulator employing serial/parallel, two's complement, carry-save arithmetic to deliver a 16-bit product in eight clock cycles. The device is fully cascadable for use in high-speed, real-time, digital signal processing applications.

The device includes an eight-bit X Register prior to the X latch providing X hold for chain or overlapping calculations. The X and Y registers are loaded by clocking prior to the beginning of a multiply cycle, the data supplied by the bidirectional bus or the accumulator register. The double length, 16-bit output is multiplexed onto the eight-bit bus; either the upper or lower halves of the result can be read at any one time.

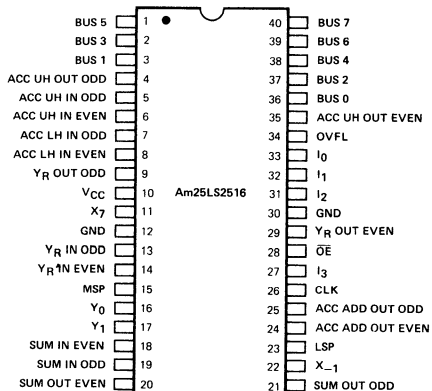
The accumulator and the Y register are both organized as dual-rank shift registers, allowing them to shift two bits at a time. The serial inputs and outputs of the Y register, the low and high order halves of the accumulator and the two-bit serial accumulator adder output, both serially and in parallel, are all available at external pins to provide cascadability.

LOGIC SYMBOL



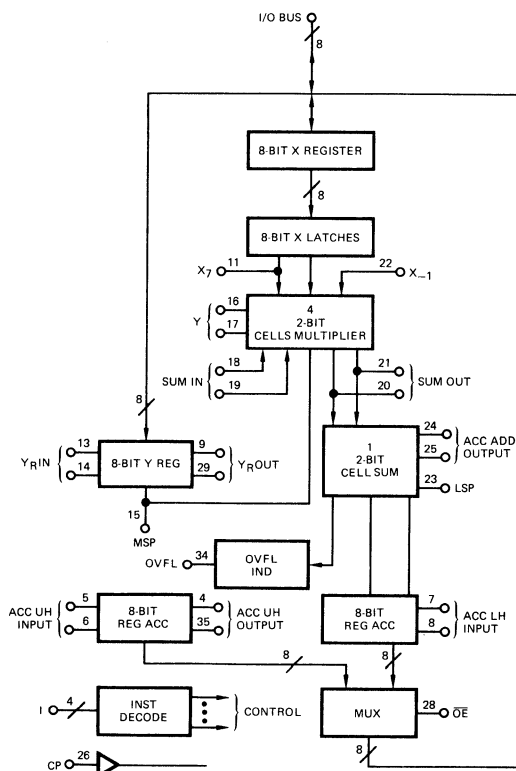
MPR-336

CONNECTION DIAGRAM



MPR-337

LOGIC DIAGRAM



MPR-338

Am25LS2516

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25VMIL $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

(Bus Inputs/Outputs)

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -1.0\text{mA}$	2.4			Volts
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4.0\text{mA}$			0.4	Volts
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		MIL		0.7	Volts
				COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$				-0.8	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$				60	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 5.5\text{V}$				0.2	mA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-30		-100	mA

3

(Non-Bus Inputs/Outputs)

V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -1.0\text{mA}$	2.5			Volts
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}		$Y_{ROUT}, I_{OL} = 15\text{mA}$		0.5	Volts
				Others $I_{OL} = 4.0\text{mA}$		0.4	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		Y_0, Y_1		0.8	Volts
				Others, MIL		0.7	
				Others, COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$		See Table 1			mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$		See Table 1			μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 5.5\text{V}$		See Table 1			mA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-30		-100	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$			230	315	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

TABLE 1

Terminals	I _{IL}	I _{IH}	I _I
Y in, I ₀ , I ₁ , I ₃ , OE	0.4mA	20μA	0.1mA
Sum in, X ₋₁ , I ₂	0.8mA	40μA	0.2mA
Bus 0-7	0.8mA	50μA	0.3mA
CP, LSP	1.6mA	80μA	0.4mA
ACC in all	2.0mA	120μA	0.6mA
MSP	2.6mA	140μA	0.7mA
Y ₀ , Y ₁	7.2mA	360μA	-2.0mA

SWITCHING CHARACTERISTICS

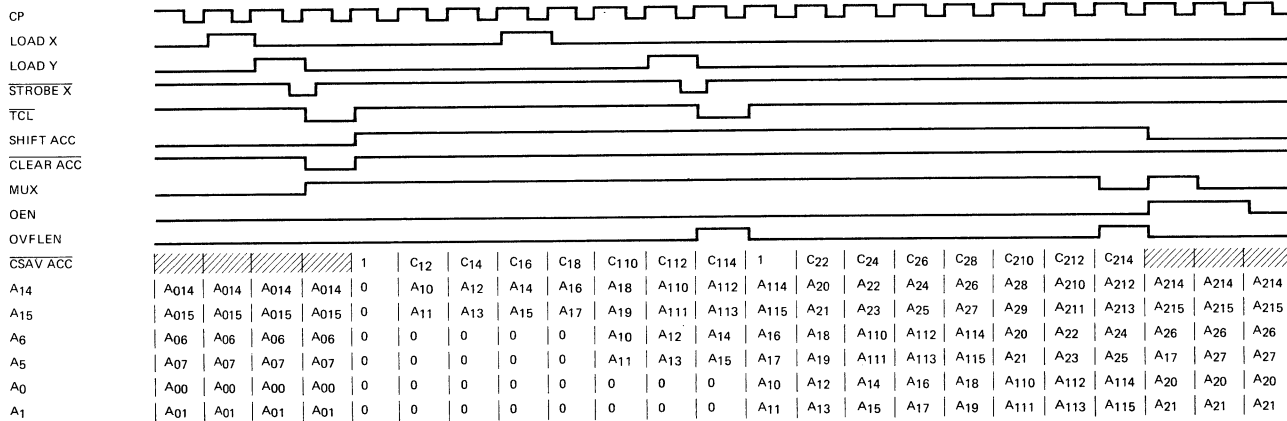
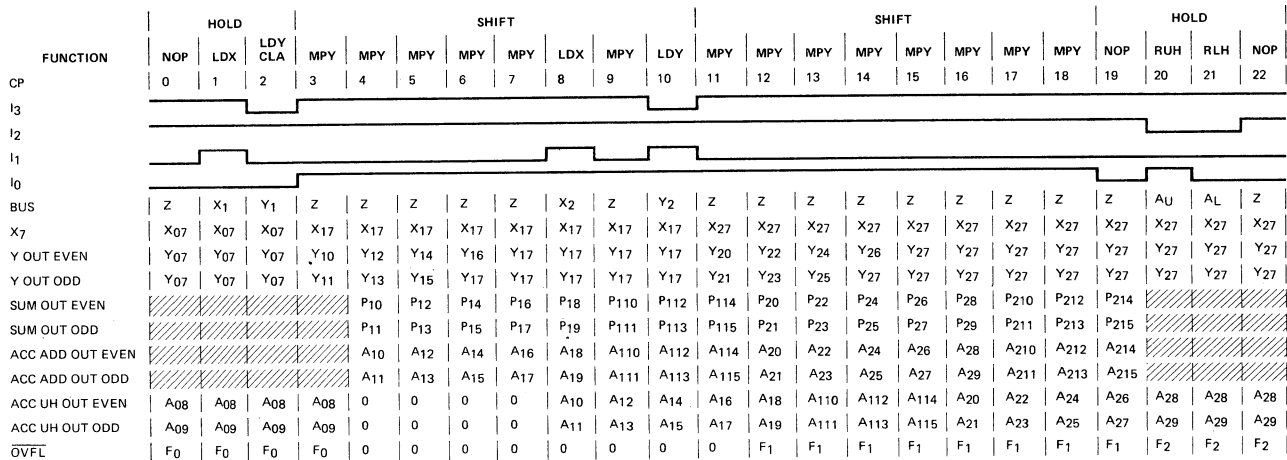
(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t _{PHL}	Y _R Register Out		15		ns	C _L = 15pF R _L = 2.0kΩ
t _{PLH}			12			
t _{PHL}	Sum Out		13		ns	
t _{PLH}			13			
t _{PHL}	ACC Adder Out		20		ns	
t _{PLH}			27			
t _{PHL}	ACC UH Out		13		ns	
t _{PLH}			12			
t _{PHL}	ACC Bus		22		ns	
t _{PLH}			25			
t _{PHL}	OVFL		17		ns	
t _{PLH}			16			
t _{PHL}	X ₇		20		ns	
t _{PLH}			15			
t _{ZH}	O _E to Bus		11		ns	
t _{ZL}			8			
t _{HZ}			28			
t _{LZ}			22			
t _S	X Register (Bus)	25			ns	C _L = 5.0pF R _L = 2.0kΩ
t _S	Y Register (Bus)	25			ns	
t _S	X - 1	33			ns	
t _S	Sum In	33			ns	
t _S	Y Register (Serial)	25			ns	
t _S	ACC LH In	8			ns	
t _S	ACC UH In	8			ns	
t _S	Y EVEN and Y ODD	33			ns	
t _S	Instruction				ns	
t _H	Hold Time on All Inputs	5			ns	

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +6.3V
DC Voltage Applied to Outputs for High Output State	-0.5V to +V _{CC} max.
DC Input Voltage (Pins 5, 6, 7, 8, 18, 19, 26)	-0.5V to +5.5V
DC Input Voltage (Other pins)	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

TIMING DIAGRAMS



KEY:
 Data invalid

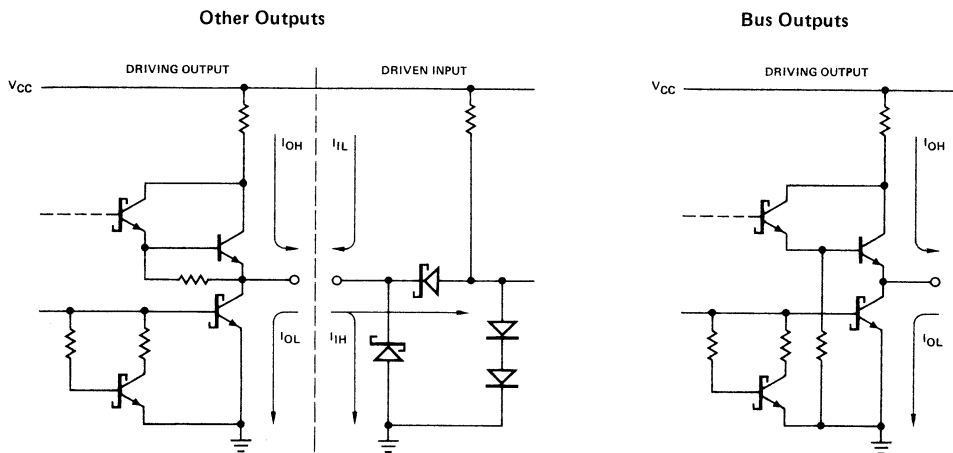
Note: Variables shown are general.
 For this example:
 $P_1 = X_1 Y_1$ $A_1 = P_1$ $F_1 = 0$
 $P_2 = X_2 Y_2$ $A_2 = P_1 + P_2$

FUNCTION TABLE

Mnemonic	I ₃ I ₂ I ₁ I ₀	Function	CLR M	LOAD X	LOAD Y	XFER X	CLR A*	SHFT A	MUX	OE	Remarks
YLHC	0 0 0 0	LHA → Y, XFER X, CLR A CLR M, READ OVFL	1	0	1	1	0	0	0	1	
YUHC	0 0 0 1	UHA → Y, XFER X, CLR A CLR M, READ OVFL	1	0	1	1	0	0	1	1	
YLHA	0 0 1 0	LHA → Y, XFER X CLR M, READ OVFL	1	0	1	1	1	0	0	1	
YUHA	0 0 1 1	UHA → Y, XFER X CLR M, READ OVFL	1	0	1	1	1	0	1	1	
LYCA	0 1 0 0	LOAD Y, XFER X, CLR A, CLR M	1	0	1	1	0	0	0	0	Same Func. as 0101
LYCA	0 1 0 1	CLR A LOAD Y, XFER X, CLR M	1	0	1	1	0	1	1	0	Same Func. as 0100
LYHA	0 1 1 0	LOAD Y, XFER X, HOLD A, CLR M	1	0	1	1	1	0	0	0	
LYSA	0 1 1 1	LOAD Y, XFER X, SHIFT A CLR M, MULTIPLY	1	0	1	1	1	1	1	0	OVFLEN in Next State
RLHA	1 0 0 0	READ LHA READ OVFL	0	0	0	0	1	0	0	1	
RUHA	1 0 0 1	READ UHA READ OVFL	0	0	0	0	1	0	1	1	
XLHA	1 0 1 0	LHA → X READ OVFL	0	1	0	0	1	0	0	1	
XUHA	1 0 1 1	UHA → X READ OVFL	0	1	0	0	1	0	1	1	
NOOP	1 1 0 0	NO OP OVFLEN AFTER MULT	0	0	0	0	1	0	0	0	Must Pre'd Any Output
MULT	1 1 0 1	MULTIPLY SHIFT A	0	0	0	0	1	1	1	0	
LXHA	1 1 1 0	LOAD X, HOLD A	0	1	0	0	1	0	0	0	
LXSA	1 1 1 1	LOAD X, SHIFT A MULTIPLY	0	1	0	0	1	1	1	0	

*Active LOW

Am25LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown

DEFINITION OF FUNCTIONAL TERMS

Bus 0-Bus 7	- Bi-directional 8-bit data bus.	Sum in even	- Multiplier input even for cascading link to more significant byte, for standalone, ground.
X7	- Interconnection link from more significant byte if cascading (output).	Sum in odd	- Multiplier input odd for cascading link to more significant byte, for standalone, ground.
X1	- Interconnecting link between devices to least significant byte if cascading (input) link X7 to X1 to cascade - must be ground if not used.	Sum out even	- Multiplier output even (link to sum in even for cascading) can be used directly.
Accum Upper Half out, even	- Accumulator output upper byte, even bit.	Sum out odd	- Multiplier output odd (link to sum output odd for cascading) can be used directly.
Accum Upper Half out, odd	- Accumulator output upper byte, odd bit.	Acc Add out, even	- Adder output even, for LSB (Hi) output equal sum of Accum and multiplier, for LSB (low) output equal sum of accumulator and zero.
Accum Upper Half input even	- Accumulator input, upper byte, even bit.	Acc Add out, odd	- Same as above except odd bit instead of even.
Accum Upper Half input odd	- Accumulator input, upper byte, odd bit.	LSB	- Control for summing adder - See Accumulator Add outputs for definition.
Accum Lower Half input even	- Accumulator input, lower byte, even bit.	I₀₋₁₃	- 4-bit instruction field - provide cycle for cycle control of device function.
Accum Lower Half input odd	- Accumulator input, lower byte, odd bit.	onfl	- Stored overflow indicator used only on least significant byte. Requires proper execution of instruction to operate.
YR out even	- "Y" register output, even (link to "Y ₀ ").	MSB	- Control for "Y" reg. and multiplier to indicate Most Significant Byte - Activates sign extension and negative waiting for 2's compliment - Low for lesser significant bytes and High for Most Significant Byte only.
YR out odd	- "Y" register output, odd (link to "Y ₁ ").	CP	- Clock Pulse
YR in even	- "Y" register input, even (link for cascading) ground when not used.	<u>OE</u>	- 3 state enable for Bus 0-Bus 7 outputs.
YR in odd	- "Y" register input, odd (link for cascading) ground when not used.		
Y₀	- Multiplier odd input (link to Y reg. odd).		
Y₁	- Multiplier even input (link to Y reg. even).		

THE Am25LS2516 LSI MULTIPLIER/ACCUMULATOR

By Roy Levy

The Am25LS2516 is an 8-bit Multiplier/Accumulator designed for medium performance, minimum power, real time signal processing applications such as digital filtering, Fast Fourier Transforms, and statistical correlation. Using two's complement carry-save arithmetic, this 40-pin LSI device delivers a 16-bit product in eight clock cycles. This will permit two devices to be cascaded to achieve a 16-bit by 16-bit multiplication in 940ns when used over the full military operating range.

A functional block diagram of the Am25LS2516 is shown in Figure 1. The key elements are an 8-bit X input register followed by an 8-bit X latch, an 8-bit Y register, four 2-bit multipliers, a 2-bit adder, two 8-bit accumulators (high order and low order), a byte selecting multiplexer and instruction decode logic. These components, equivalent to approximately 625 gate elements, are integrated onto a single chip fabricated using Advanced Micro Devices' high-performance, Low-Power Schottky technology. The on-chip accumulator is provided to minimize component count and power dissipation in a high density system. It also allows completion of a multiply and accumulate operation in the same time normally required for a multiply only. Other LSI multipliers currently available require the accumulator function to be provided externally.

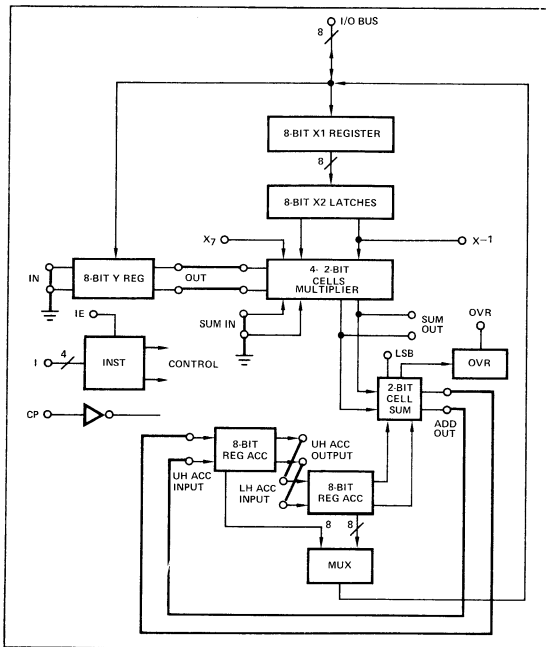


Figure 1. 8-Bit by 8-Bit Multiplier Block Diagram with External Connections Required to Accumulate A 16-Bit Product.

MULTIPLIER OPERATION

The Am25LS2516 is configured around an eight-line common input/output bidirectional bus. X and Y input and accumulator output data are routed via these bus lines. A two-rank register/latch combination is used for the X input to allow chaining of successive multiplies without losing a clock pulse; i.e., multiply and load vs. multiply. The latch holds the "X" data for the multiplier, allowing the X register to be loaded during any remaining multiply cycles. The "Y" Register can be parallel loaded, by command, from the 8-bit, on-chip bus from either the incoming 8 bits, or the Accumulator High or Accumulator Low Register (separate commands). The "Y" Register provides the 2-bit-at-a-time shift and the sign extend which allows the four 2-bit cells to operate in a serial by parallel mode. The multiplier produces a 2-bit product for each clock, LSB's first. Its output is accepted by the 2-bit adder as well as presented to external pins for expansion. A control gating array is provided to test for overflow during the last add cycle of the operation; i.e., cycle 8 for 8-bit multiply and cycle 16 for 16-bit multiply. The timing and control of this specific cycle is accomplished by the microcode chosen. The "no-op" and "LYSA" instructions are provided for this purpose. The first cycle of a no-op following a multiply will cause the results of the overflow test to be stored. Two 8-bit accumulators are provided which must be externally connected in either an 8-bit, 16-bit, or greater configuration.

These accumulators as well as the Y Register, are both organized as dual-rank shift registers, which allow them to shift two bits at a time. The serial inputs and outputs of the Y Register and the low and high order halves of the accumulator are all brought out to external pins for cascading the device.

The accumulator output is available both serially and in parallel. The accumulator results are available one bit later than the multiply cycle and the accumulator stops shifting during read cycles. If the device is used to compute $X \cdot Y$ products without accumulation, a minimum of two overhead cycles must accompany each multiply - one for reading the upper (lower) half of the accumulator and one for clearing of the accumulator during the loading of the X or Y Registers. An output multiplexer selects the high or low order accumulator contents for presentation to the bus in parallel 8 bits at a time.

The heart of this device is an 8-bit multiplier (Figure 2) made up of four 2-bit cells. Each cell has three inputs (2 bits wide), two dual carry-save full adders, with four flip-flops for temporary storage (two for carry-save and two for partial product). The multiplier is actually subdivided into two separate adders with appropriate carry-save. The last adder forms a partial sum representing $0, 1X, 2X,$ or $3X$ by using combinations of X and $2X$. The control of this combination is Y_0 and Y_1 , respectively, to form $Y_0X_n + Y_1X_{n+1}$. This sum (nX) is the input for the second adder. The second adder combines the first adder (nX) sum with the stored partial product

shifted two places plus carry to form a new partial product.

$$P_{0MSB} + \sum_0 + C = P_{0LSB}$$

$$P_{1MSB} + \sum_1 + C = P_{1LSB}$$

The two partial product bits of the least significant cell are made available to the SUMmer and the SUM out terminals. The LSB input controls the SUM out providing a pass through or add dependent on polarity.

PROGRAMMING THE MULTIPLIER

The Am25LS2516 is an externally programmed device controlled by four instruction lines. This programmability provides a key to its flexibility. Sixteen microinstructions (see Table 1) are provided, which can be grouped into three major functions: Data Move, Read, and Multiply.

Instruction 0-4: The first instructions ("0", "1", "2", "3") load the "Y" Register from the Accumulator (high or low), load the "X" Register while either clearing or not clearing, respectively, the Accumulator.

The next four instructions ("4", "5", "6", "7") load the "Y" Register from external "bus" and Holds on the accumulators and multiplier.

Instruction "7" is unique and is used to execute a chain multiply. It provides the last multiply operation while loading the "Y" Register, transferring the "X", and clearing the multiplier.

Instructions "8" and "9" provide the read-out (upper and lower halves) of the Accumulator.

Instructions "A" and "B" internally transfer the respective halves of the Accumulator to the "X" Register – another method of chain calculating.

Instruction "C" is a true no-op and provides an idling instruction without disabling the clock. NOTE: The operations of the instruction are in some cases stored by clocking the instructions into an instruction register, accounting for a

clocked delay in operations. Specifically, the shifting of the Accumulator is an internally stored command and as such is started and stopped one clock cycle late, allowing the Accumulator to complete its data shifting during the first no-op cycle following a multiply and starting it one clock cycle after the multiplying cycle is started.

Instruction "D" is a single iteration of the multiply and must be used for each bit in the multiplier minus one. The last bit of the multiplier will be handled by a no-op ("C") or a load Y and multiply (7).

TABLE I

MNEMONIC	INSTRUCTION 3 2 1 0 IN HEX	FUNCTION	REMARKS
YLHC	0	LHA → Y, XFER X, CLR A CLR M, READ OVFL	
YUHC	1	UHA → Y, XFER X, CLR A CLR M, READ OVFL	
YLHA	2	LHA → Y, XFER X CLR M, READ OVFL	
YUHA	3	UHA → Y, XFER X CLR M, READ OVFL	
LYCA	4	LOAD Y, XFER X, CLR A CLR M	Same function as 5
LYCA	5	CLR A LOAD Y, XFER X, CLR M	Same function as 4
LYHA	6	LOAD Y, XFER X, HOLD A CLR M	
LYSA	7	LOAD Y, XFER X, SHIFT A CLR M, MULTIPLY	Enables overflow store in next state *
RLHA	8	READ LHA READ OVFL	
RUHA	9	READ UHA READ OVFL	
XLHA	A	LHA → X READ OVFL	
XUHA	B	UHA → Y READ OVFL	
NOOP	C	NO OP	Enable overflow store
MULT	D	MULTIPLY SHIFT A	*
LXHA	E	LOAD X, HOLD A	
LXSA	F	LOAD X, SHIFT A MULTIPLY	*

*Continue multiplying instructions

3

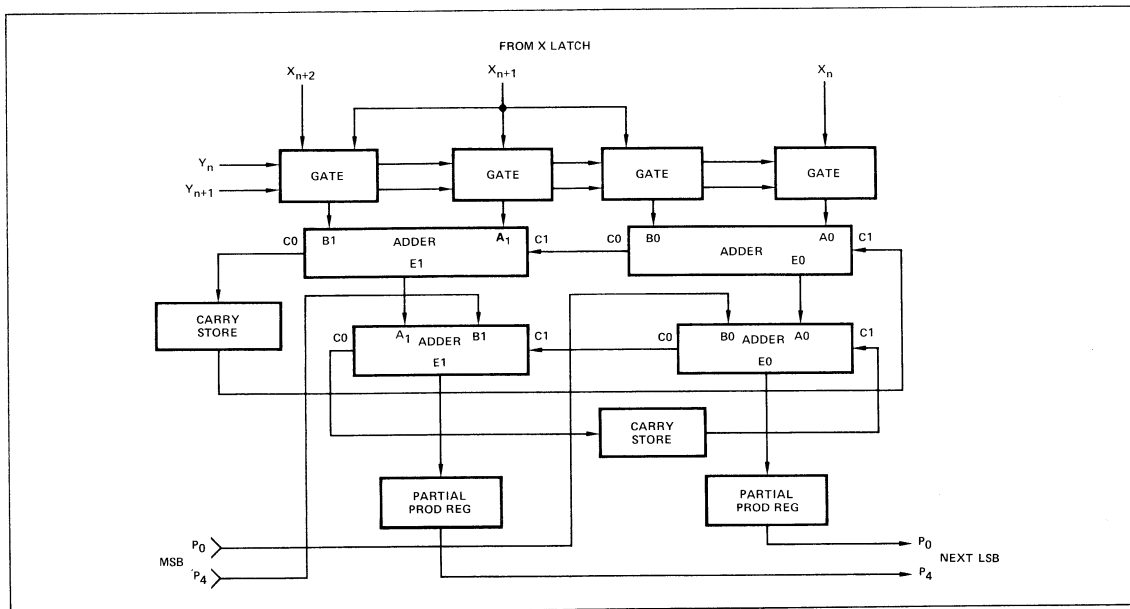


Figure 2. Am25LS2516 Multiplier Cell.

Instruction "E" provides a load "X" Register and Hold.

Instruction "F" provides an intermediate instruction which can be executed during a multiply. It allows the "X" Register to load without disturbing the "X" Latch, while continuing the iteration of the multiply.

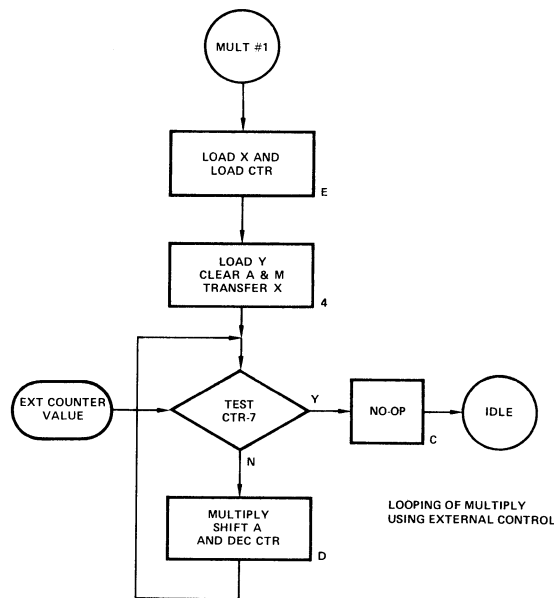
Instructions "C" and "7" also provide sampling and storage of the overflow condition.

APPLICATION OF THE MULTIPLIER

The flow diagram for an 8-bit two's complement multiply is shown in Figure 3, together with the required program micro-steps. Figure 4 extends this to include accumulate, intermediate load of X and chain calculations. Figures 5a and b show the external connection of two Am25LS2516 devices to execute a 16-bit by 16-bit multiplication. A 32-bit product is

completed in 16 clock cycles. This same technique may be extended in a similar fashion to longer word lengths. The flowchart of Figure 6 demonstrates a 16-bit two's complement multiply without accumulate, modified to a 12-bit by 12-bit function.

The Am25LS2516 Multiplier/Accumulator is the most complex LSI product manufactured to date with Low Power Schottky technology. It will be extremely useful in high-density applications where minimum package count is a primary consideration. The device itself performs an 8 x 8 or 16 x 16 multiplication in approximately twice the time of parallel multipliers currently available, but using only one quarter the power in the multiplier portion of the function. In a fully configured system using both techniques, the Am25LS2516 performance begins to approach that of the parallel multiplier plus supporting devices.



PROGRAM MICRO STEPS

#	INST IN HEX
1	E
2	4
3	D
4	D
5	D
6	D
7	D
8	D
9	D
10	C
	IDLE

Figure 3. 8-Bit Two's Complement Multiply without Accumulate or Chain.

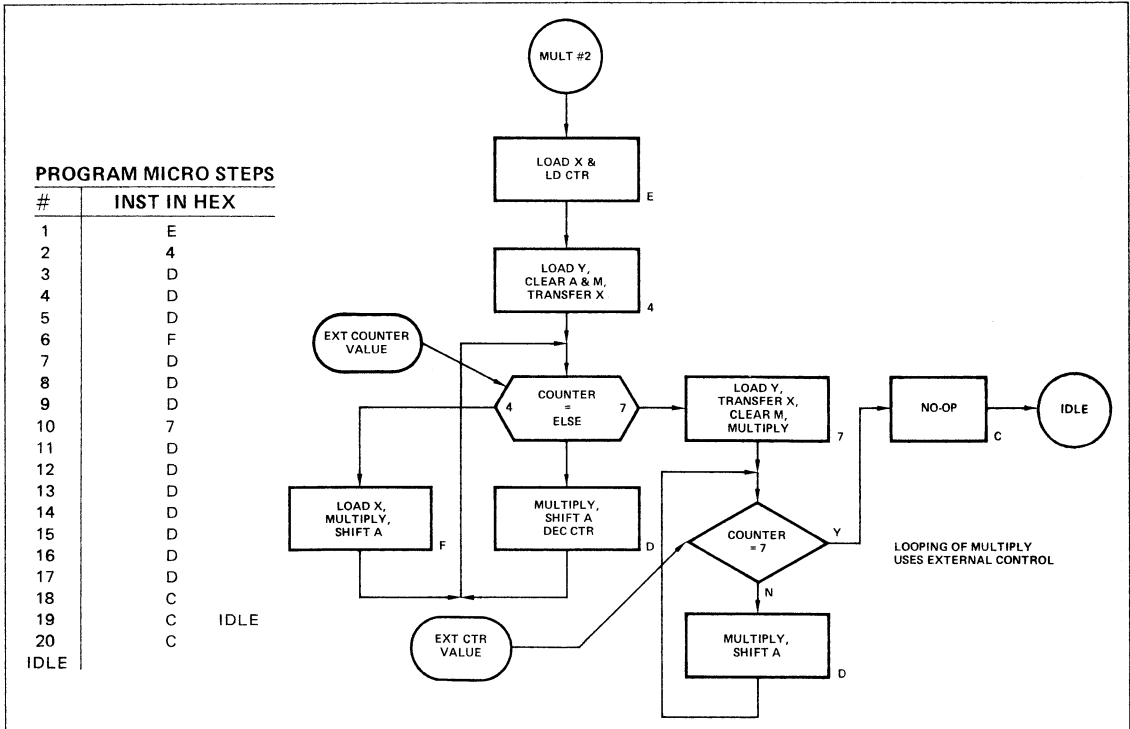


Figure 4. 8-Bit Two's Complement Multiply with Accumulate, Intermediate Load and Chain Calculations.

3

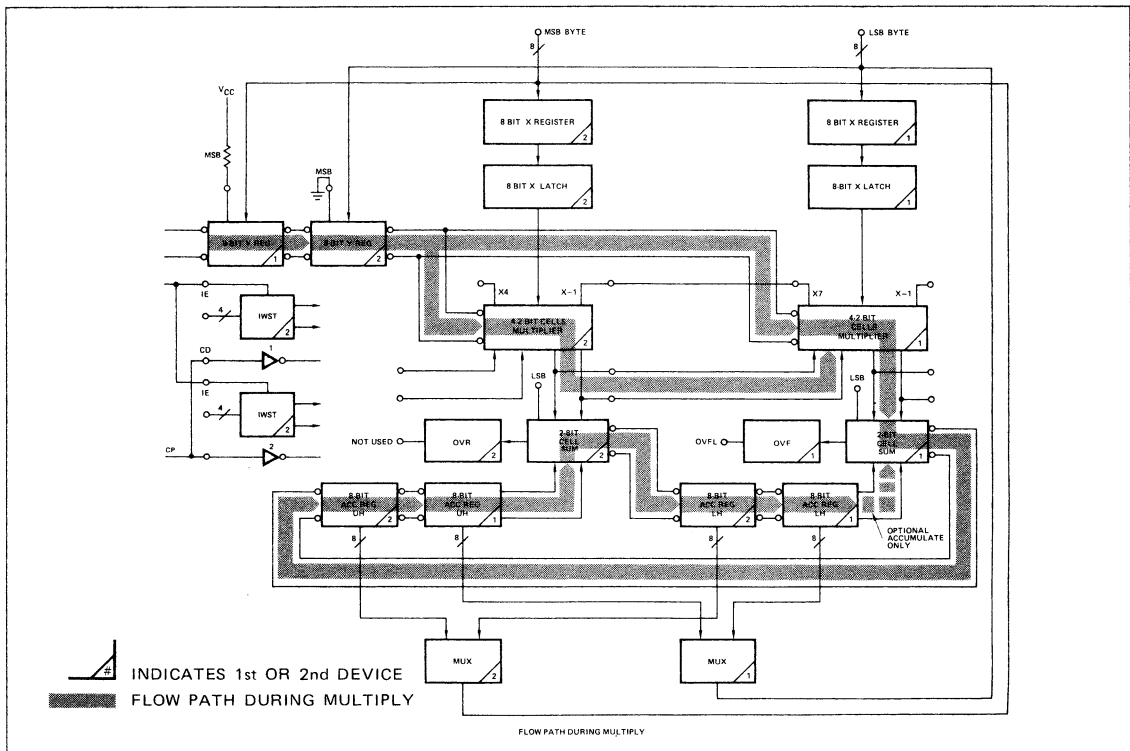


Figure 5a. Interconnection of Two Am25LS2516 (8 x 8 Multiplier) Devices to Execute a 16 x 16 Multiply.

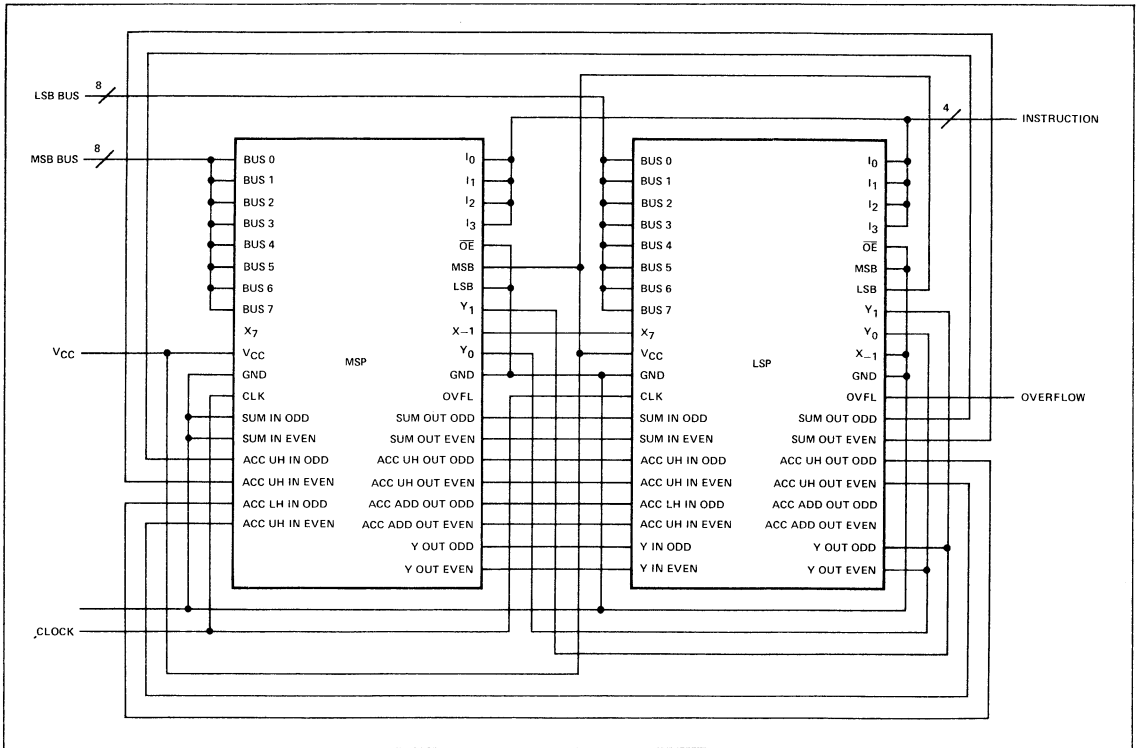


Figure 5b. Two Devices Cascaded in 16-Bit by 16-Bit Multiplier Application with 32-Bit Accumulated Product.

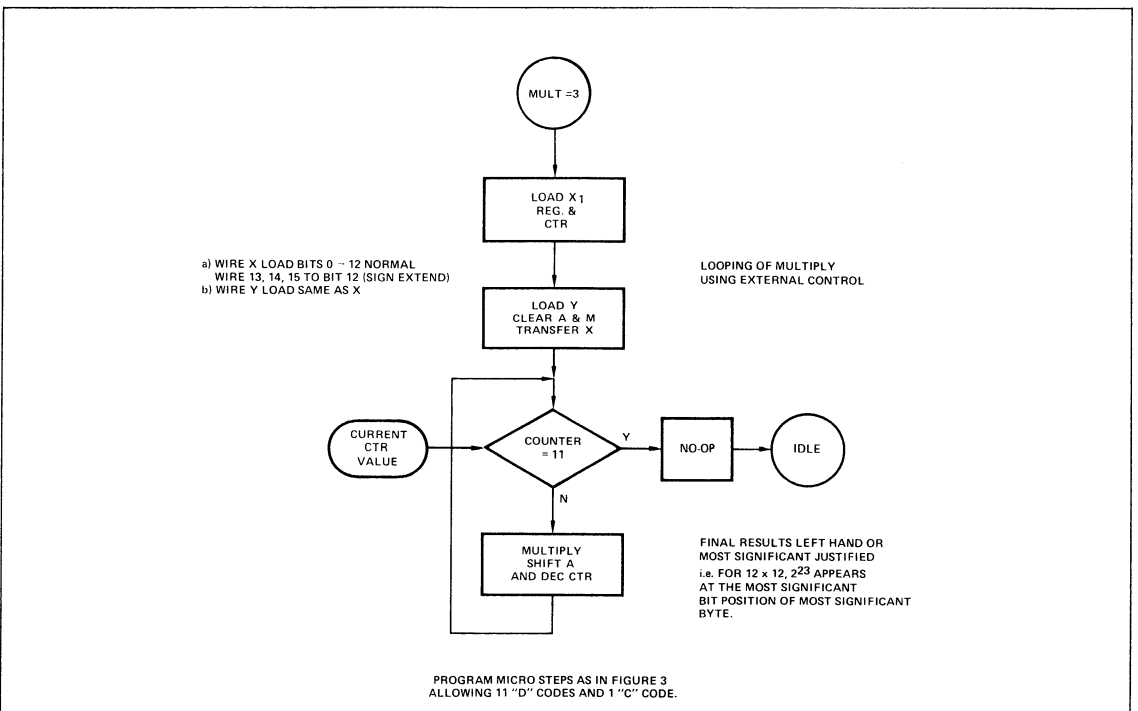


Figure 6. 16 Bit Two's Complement Multiply without Accumulate Modified to 12 x 12 (Using Two Am25LS2516 Interconnected).

Am25LS2517

Arithmetic Logic Unit/Function Generator

Am25LS2517 data is combined with the Am25LS381.

See Am25LS381 data sheet for full information.

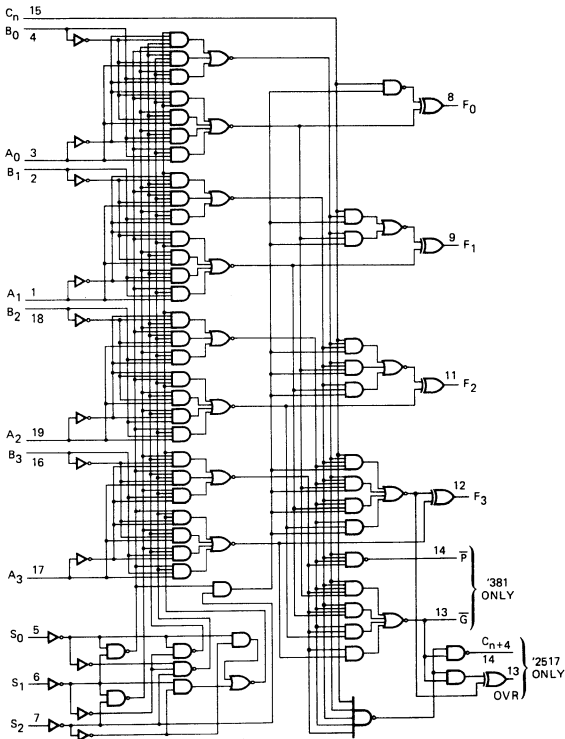
FUNCTIONAL DESCRIPTION

The Am25LS381 and Am54LS/74LS381 are arithmetic logic units (ALU)/function generators that perform three arithmetic operations and three logic operations on two 4-bit words. The device can also output forced 0000 (clear) or 1111 (preset). These eight operations are selected using three function select inputs S_0 , S_1 and S_2 as shown in the function table. Full carry look ahead is used over the four-bit field within the device. When devices are cascaded, multi-level full carry look-ahead is implemented using a '182 carry look ahead generator and the \bar{G} and \bar{P} outputs on the Am25LS381 or Am54LS/74LS381. The device is packaged in a space-saving (0.3-inch row spacing) 20-pin package. If the C_{n+4} carry output function is required, the Am25LS2517 should be used.

The Am25LS381 is a high-performance version of the Am54LS/74LS381. Improvements include faster a. c. specifications, higher noise margin and twice the fan-out over the military temperature range.

The Am25LS2517 is an arithmetic logic unit (ALU)/function generator that performs three arithmetic operations and three logic operations on two 4-bit words. The device can also force output 0000 (clear) or 1111 (preset). These eight operations are selected using three function select inputs S_0 , S_1 and S_2 as shown in the function table. Full carry look-ahead is used over the four-bit field within the device. When devices are cascaded, the carry output (C_{n+4}) is connected to the carry input (C_n) of the next device. The Am25LS2517 can also detect two's complement overflow. The overflow output (OVR) is defined logically as $C_{n+3} \oplus C_{n+4}$.

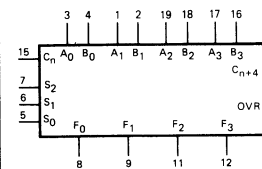
LOGIC DIAGRAM



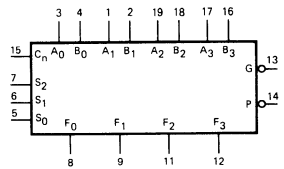
Note: The Advanced Micro Devices' LS381 products were designed prior to publication of data sheets by T.I. Review specifications for possible differences.

LOGIC SYMBOLS

Am25LS2517



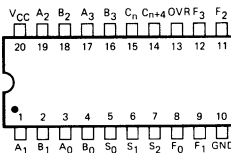
Am25LS381
Am54LS/74LS381



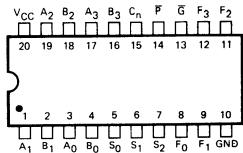
V_{CC} = Pin 20
GND = Pin 10

CONNECTION DIAGRAMS Top Views

Am25LS2517



Am25LS381
Am54LS/74LS381



Note: Pin 1 is marked for orientation.

3

Am25LS2518

Quad D Register With Standard And Three-State Outputs

DISTINCTIVE CHARACTERISTICS

- Low-power Schottky version of the popular Am2918 and Am25S18
- Four standard totem-pole outputs
- Four three-state outputs
- Four D-type flip-flops
- Second sourced by T. I. as the SN54/74LS388
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am25LS2518 consists of four D-type flip-flops with a buffered common clock. Information meeting the set-up and hold requirements on the D inputs is transferred to the Q outputs on the LOW-to-HIGH transition of the clock.

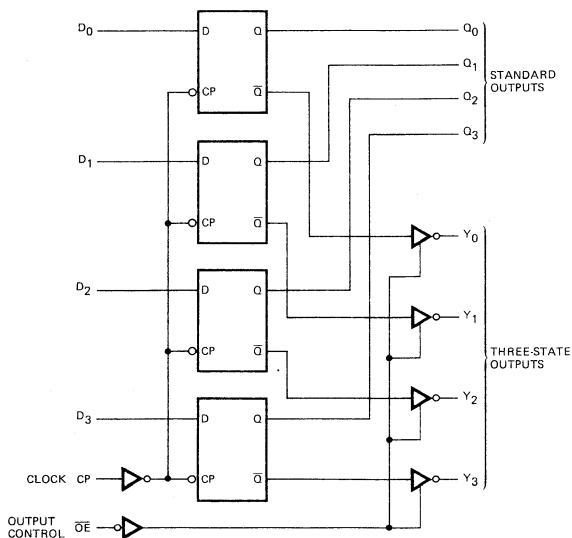
The same data as on the Q outputs is enabled at the three-state Y outputs when the "output control" (\overline{OE}) input is LOW. When the \overline{OE} input is HIGH, the Y outputs are in the high-impedance state.

The Am25LS2518 is a 4-bit, high-speed register intended for use in real-time signal processing systems where the standard outputs are used in a recursive algorithm and the three-state outputs provide access to a data bus to dump the results after a number of iterations.

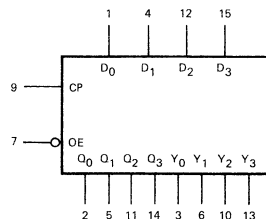
The device can also be used as an address register or status register in computers or computer peripherals.

Likewise, the Am25LS2518 is also useful in certain display applications where the standard outputs can be decoded to drive LED's (or equivalent) and the three-state outputs are bus organized for occasional interrogation of the data as displayed.

LOGIC DIAGRAM

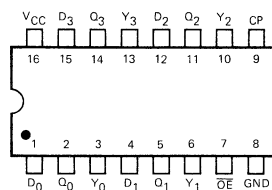


LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

Am25LS2518

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25VMIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	O, $I_{OH} = -660\mu\text{A}$	MIL	2.5	3.4	Volts
				COM'L	2.7	3.4	
		Y	MIL, $I_{OH} = -1.0\text{mA}$	2.4	3.4		
			COM'L, $I_{OH} = 2.6\text{mA}$	2.4	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.4	Volts	
			$I_{OL} = 8.0\text{mA}$		0.45		
			$I_{OL} = 12\text{mA}$		0.5		
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$			-0.36	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$			20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 7.0\text{V}$			0.1	mA	
I_{OZ}	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$		-20	μA	
			$V_O = 2.4\text{V}$		20		
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		17	28	mA	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. I_{CC} is measured with all inputs at 4.5V and all outputs open.

3

Am25LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to + V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am25LS2518

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	Clock to Q_i		18	27	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			18	27		
t_{PLH}	Clock to Y_i (\overline{OE} LOW)		18	27	ns	
t_{PHL}			18	27		
t_{pw}	Clock Pulse Width	LOW	18		ns	
		HIGH	15			
t_s	Data	15			ns	
t_h	Data	5.0			ns	
t_{ZH}	\overline{OE} to Y_i		7.0	11	ns	
t_{ZL}			8	12		
t_{HZ}	\overline{OE} to Y_i		14	21	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{LZ}			12	18		
f_{max}	Maximum Clock Frequency (Note 1)	35	50		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r , t_f , pulse width or duty cycle.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$			
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to Q_i		38		45	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			38		45		
t_{PLH}	Clock to Y_i (\overline{OE} LOW)		35		40	ns	
t_{PHL}			35		40		
t_{pw}	Clock Pulse Width	LOW	20		20	ns	
		HIGH	20		20		
t_s	Data	15		15		ns	
t_h	Data	5.0		5.0		ns	
t_{ZH}	\overline{OE} to Y_i		15		17	ns	
t_{ZL}			16		17		
t_{HZ}	\overline{OE} to Y_i		27		30	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{LZ}			24		30		
f_{max}	Maximum Clock Frequency (Note 1)	30		25		MHz	

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

D_i The four data inputs to the register.

Q_i The four data outputs of the register with standard totem-pole active pull-up outputs. Data is passed non-inverted.

Y_i The four three-state data outputs of the register. When the three-state outputs are enabled, data is passed non-inverted. A HIGH on the "output control" input forces the Y_i outputs to the high-impedance state.

CP Clock. The buffered common clock for the register. Enters data on the LOW-to-HIGH transition.

\overline{OE} Output Control. When the \overline{OE} input is HIGH, the Y_i outputs are in the high-impedance state. When the \overline{OE} input is LOW, the TRUE register data is present at the Y_i outputs.

TRUTH TABLE

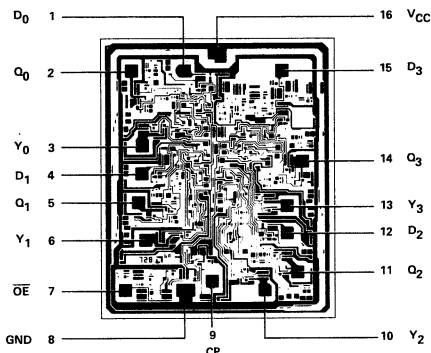
INPUTS			OUTPUTS		NOTES
\overline{OE}	CLOCK CP	D	Q	Y	
H	L	X	NC	Z	—
H	H	X	NC	Z	—
H	↑	L	L	Z	—
H	↑	H	H	Z	—
L	↑	L	L	L	—
L	↑	H	H	H	—
L	—	—	L	L	1
L	—	—	H	H	1

L = LOW
H = HIGH
X = Don't care

NC = No change
↑ = LOW to HIGH transition
Z = High impedance

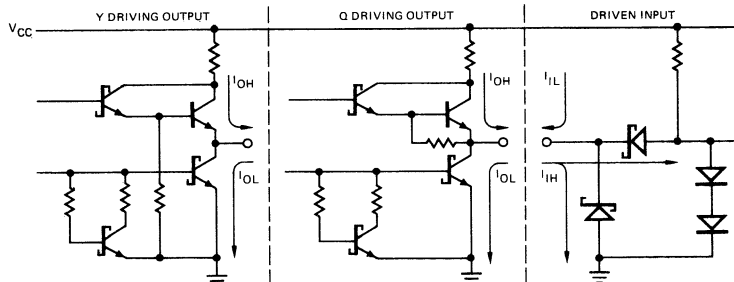
Note: 1. When \overline{OE} is LOW, the Y output will be in the same logic state as the Q output.

Metallization and Pad Layout



DIE SIZE 0.083" X 0.099"

**Am25LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**



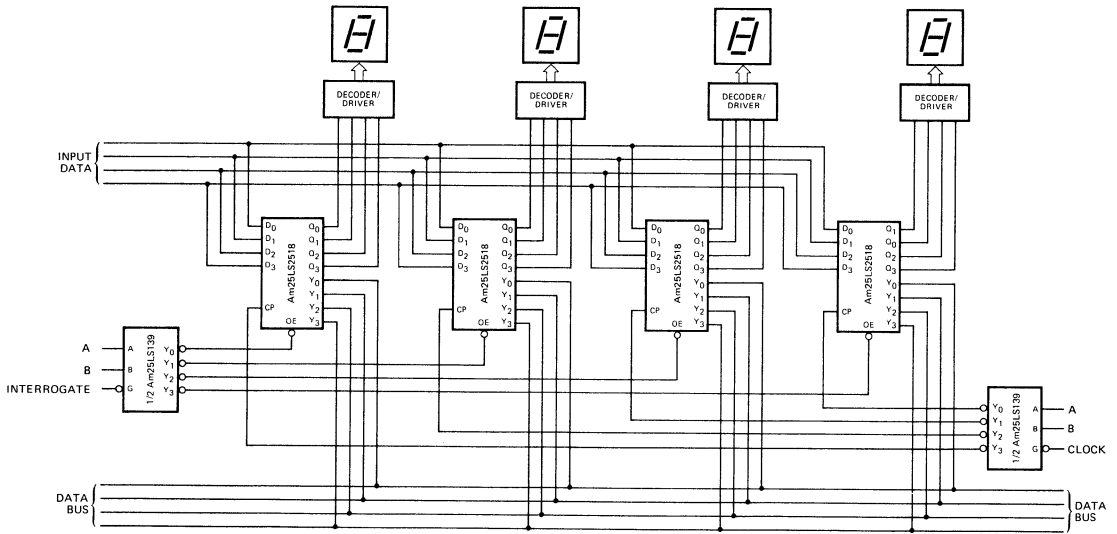
Note: Actual current flow direction shown.

3

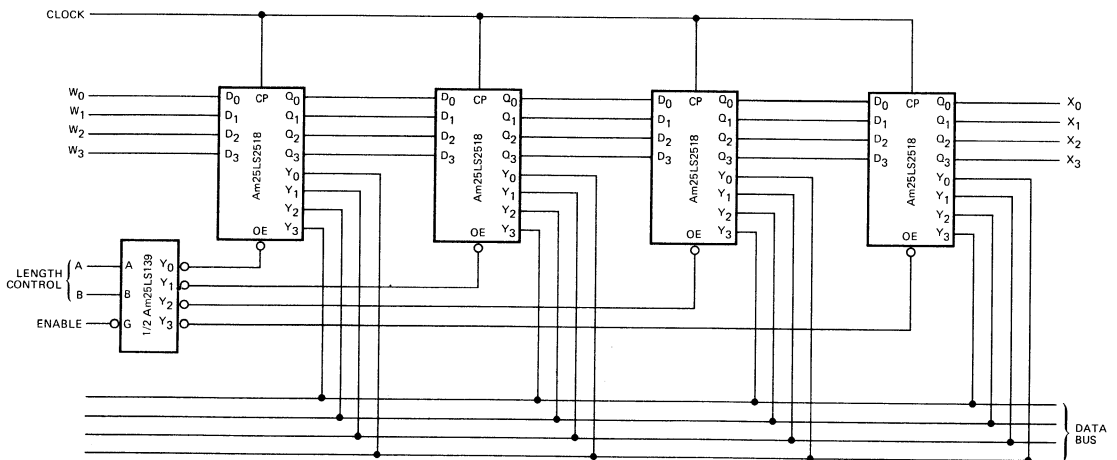
ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM25LS2518PC
Hermetic DIP	0°C to +70°C	AM25LS2518DC
Dice	0°C to +70°C	AM25LS2518XC
Hermetic DIP	-55°C to +125°C	AM25LS2518DM
Hermetic Flat Pak	-55°C to +125°C	AM25LS2518FM
Dice	-55°C to +125°C	AM25LS2518XM

APPLICATIONS



The Am25LS2518 used as display register with bus interrogate capability.



The Am25LS2518 as a variable length (1, 2, 3 or 4 word) shift register.

Am25LS2519

Quad Register With Two Independently Controlled Three-State Outputs

DISTINCTIVE CHARACTERISTICS

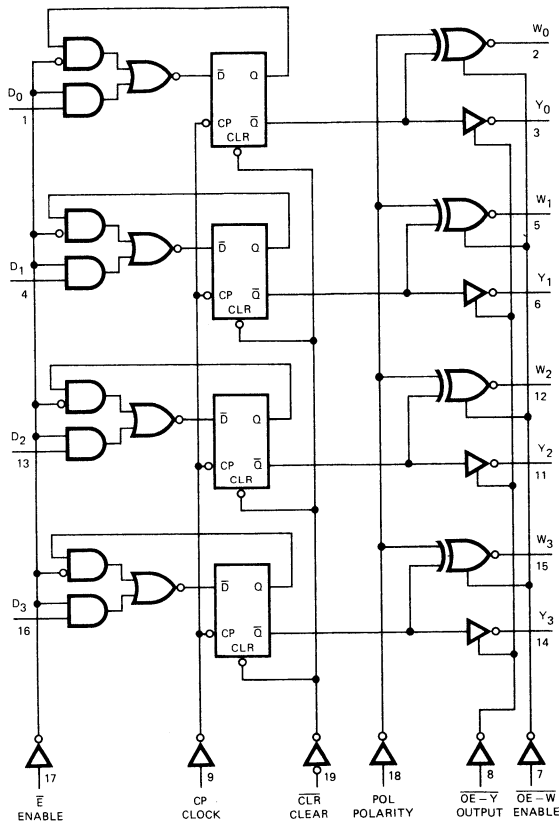
- Two sets of fully buffered three-state outputs
- Four D-type flip-flops
- Polarity control on W outputs
- Buffered common clock enable
- Buffered common asynchronous clear
- Separate buffered common output enable for each set of outputs
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

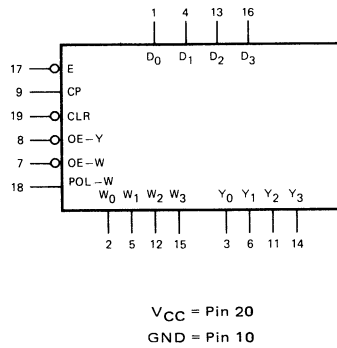
The Am25LS2519 consists of four D-type flip-flops with a buffered common clock enable. Information meeting the set-up and hold time requirements of the D inputs is transferred to the flip-flop outputs on the LOW-to-HIGH transition of the clock. Data on the Q outputs of the flip-flops is enabled at the three-state outputs when the output control (\overline{OE}) input is LOW. When the appropriate \overline{OE} input is HIGH, the outputs are in the high impedance state. Two independent sets of outputs – W and Y – are provided such that the register can simultaneously and independently drive two buses. One set of outputs contains a polarity control such that the outputs can either be inverting or non-inverting.

The device also features an active LOW asynchronous clear. When the clear input is LOW, the Q output of the internal flip-flops are forced LOW independent of the other inputs. The Am25LS2519 is packaged in a space saving (0.3-inch row spacing) 20-pin package.

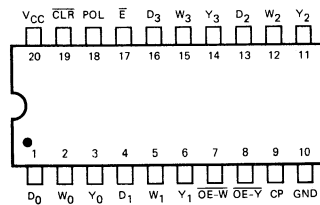
LOGIC DIAGRAM



LOGIC SYMBOL



CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

Am25LS2519

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25V
 MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL, $I_{OH} = -1.0\text{mA}$	2.4	3.4	Volts
			COM'L, $I_{OH} = -2.6\text{mA}$	2.4	3.4	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.4	Volts
			$I_{OL} = 8.0\text{mA}$		0.45	
			$I_{OL} = 12\text{mA}$		0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$			-0.36	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$			20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$			0.1	mA
I_{OZ}	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$		-20	μA
			$V_O = 2.4\text{V}$		20	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$	MIL	24	36	mA
			COM'L	24	39	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Inputs grounded; outputs open.

Am25LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to $+V_{CC}$ max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

SWITCHING CHARACTERISTICS

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t _{PHL}	Clock to Y _i		22	33	ns	C _L = 15pF R _L = 2.0kΩ
t _{PLH}			20	30		
t _{PLH}	Clock to W _i (Either Polarity)		24	36	ns	
t _{PHL}			24	36		
t _{PHL}	Clear to Y _i		29	43	ns	
t _{PLH}	Clear to W _i		25	37	ns	
t _{PHL}			30	45		
t _{PLH}	Polarity to W _i		23	34	ns	
t _{PHL}			25	37		
t _{pw}	Clear	18			ns	
t _{pw}	ClockPulseWidth	LOW	15		ns	
		HIGH	18			
t _s	Data	15			ns	
t _h	Data	5			ns	
t _s	Data Enable	20			ns	
t _h	Data Enable	0			ns	
t _s	Set-up Time, Clear Recovery (Inactive) to Clock	20	15		ns	
t _{ZH}	Output Enable to W or Y		11	17	ns	
t _{ZL}			13	20		
t _{HZ}	Output Enable to W or Y		13	20	ns	C _L = 5.0pF R _L = 2.0kΩ
t _{LZ}			11	17		
f _{max}	Maximum Clock Frequency (Note 1)	35	45		MHz	C _L = 15pF R _L = 2.0kΩ

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

3

SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	Clock to Y _i		39		42	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			39		45		
t _{PLH}	Clock to W _i (Either Polarity)		41		43	ns	
t _{PHL}			44		48		
t _{PHL}	Clear to Y _i		52		58	ns	
t _{PLH}	Clear to W _i		42		43	ns	
t _{PHL}			51		53		
t _{PLH}	Polarity to W _i		41		45	ns	
t _{PHL}			42		44		
t _{pw}	Clear	20		20		ns	
t _{pw}	Clock	LOW	20		20	ns	
		HIGH	20		20		
t _s	Data	15		15		ns	
t _h	Data	10		10		ns	
t _s	Data Enable	25		25		ns	
t _h	Data Enable	0		0		ns	
t _s	Set-up Time, Clear Recovery (Inactive) to Clock	23		24		ns	
t _{ZH}	Output Enable to W _i or Y _i		24		27	ns	
t _{ZL}			29		35		
t _{HZ}	Output Enable to W _i or Y _i		33		45	ns	C _L = 5.0pF R _L = 2.0kΩ
t _{LZ}			22		26		
f _{max}	Maximum Clock Frequency (Note 1)	30		25		MHz	C _L = 50pF R _L = 2.0kΩ

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

FUNCTION TABLE

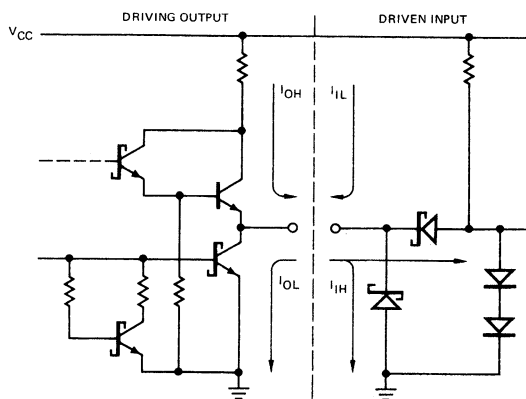
FUNCTION	INPUTS							INTERNAL	OUTPUTS	
	CP	D _i	\bar{E}	CLR	POL	OE-W	OE-Y	Q	W _i	Y _i
Output Three-State Control	X	X	X	X	X	H	L	NC	Z	Enabled
	X	X	X	X	X	L	H	NC	Enabled	Z
	X	X	X	X	X	H	H	NC	Z	Z
	X	X	X	X	X	L	L	NC	Enabled	Enabled
W _i Polarity	X	X	X	X	L	L	L	NC	Non-Inverting	Non-Inverting
	X	X	X	X	H	L	L	NC	Inverting	Non-Inverting
Asynchronous Clear	X	X	X	L	L	L	L	L	L	L
	X	X	X	L	H	L	L	L	H	L
Clock Enabled	†	X	H	H	X	X	X	NC	NC	NC
	†	L	L	H	L	L	L	L	L	L
	†	L	L	H	H	L	L	L	H	L
	†	H	L	H	L	L	L	H	H	H
	†	H	L	H	H	L	L	H	L	H

L = LOW
H = HIGH
Z = High Impedance
X = Don't Care
NC = No Change
† = LOW to HIGH Transition

DEFINITION OF FUNCTIONAL TERMS

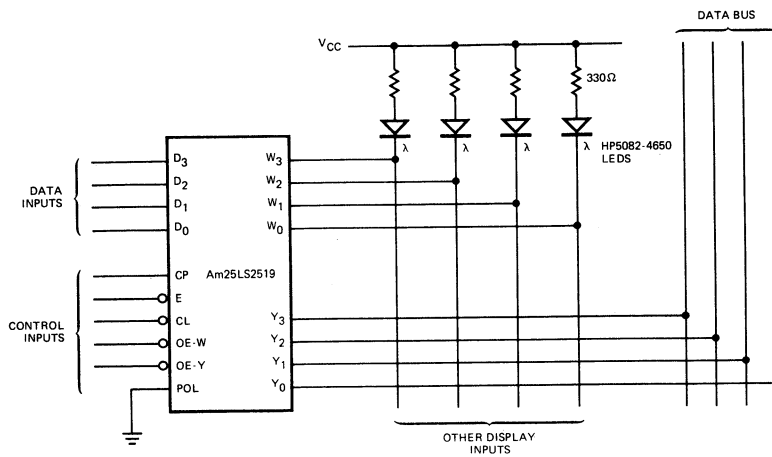
- D_i** Any of the four D flip-flop data lines.
- \bar{E}** Clock Enable. When LOW, the data is entered into the register on the next clock LOW-to-HIGH transition. When HIGH, the data in the register remains unchanged, regardless of the data in.
- CP** Clock Pulse. Data is entered into the register on the LOW-to-HIGH transition.
- $\overline{OE-W}$, $\overline{OE-Y}$** Output Enable. When \bar{OE} is LOW, the register is enable to the output. When HIGH, the output is in the high-impedance state. The $\overline{OE-W}$ controls the W set of outputs, and $\overline{OE-Y}$ controls the Y set.
- Y_i** Any of the four non-inverting three-state output lines.
- W_i** Any of the four three-state outputs with polarity control.
- POL** Polarity Control. The W_i outputs will be non-inverting when POL is LOW, and when it is HIGH, the outputs are inverting.
- CLR** Asynchronous Clear. When CLR is LOW, the internal Q flip-flops are reset to LOW.

Am25LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

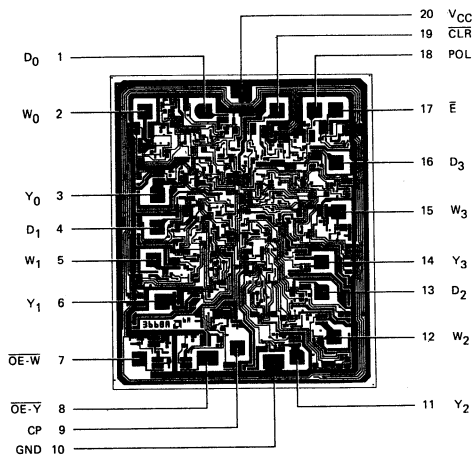
APPLICATION



Convenient Register Content Monitor or Test Point

3

Metallization and Pad Layout



DIE SIZE 0.083" X 0.099"

Am25LS2520

Octal D-Type Flip-Flop With Clear, Clock Enable And Three-State Control

DISTINCTIVE CHARACTERISTICS

- Buffered common clock enable input
- Buffered common asynchronous clear input
- Three-state outputs
- 8-bit, high-speed parallel register with positive edge-triggered, D-type flip-flops
- Am25LS Family offers improved sink current, source current and noise margin
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am25LS2520 is an 8-bit register built using advanced Low-Power Schottky technology. The register consists of eight D-type flip-flops with a buffered common clock, a buffered common clock enable, a buffered asynchronous clear input, and three-state outputs.

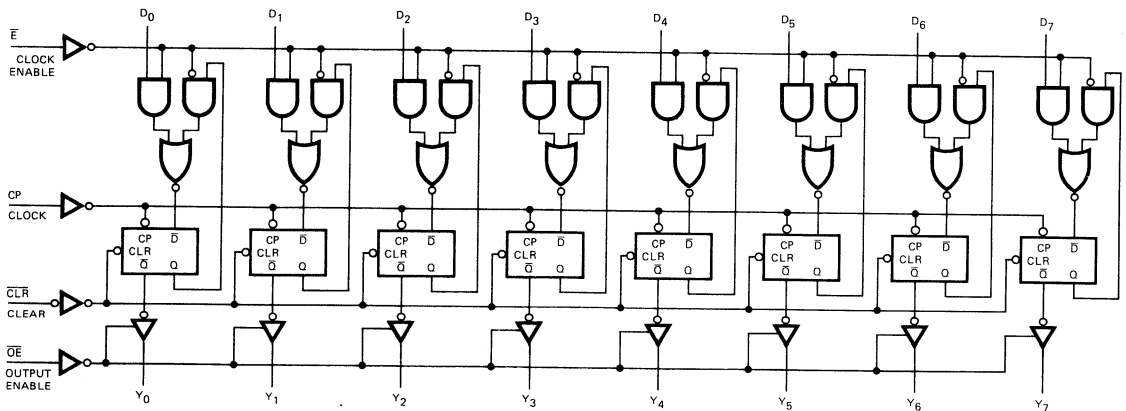
When the clear input is LOW, the internal flip-flops of the register are reset to logic 0 (LOW), independent of all other inputs. When the clear input is HIGH, the register operates in the normal fashion.

When the three-state output enable (\overline{OE}) input is LOW, the Y outputs are enabled and appear as normal TTL outputs. When the output enable (\overline{OE}) input is HIGH, the Y outputs are in the high impedance (three-state) condition. This does not affect the internal state of the flip-flop Q output.

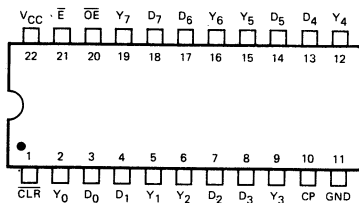
The clock enable input (\overline{E}) is used to selectively load data into the register. When the \overline{E} input is HIGH, the register will retain its current data. When the \overline{E} is LOW, new data is entered into the register on the LOW-to-HIGH transition of the clock input.

This device is packaged in a space-saving (0.4-inch row spacing) 22-pin package.

LOGIC DIAGRAM

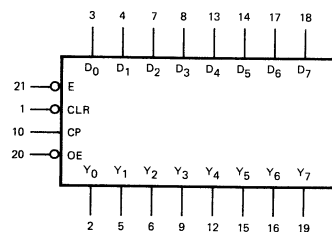


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 22
GND = Pin 11

Am25LS2520

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 VMIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN. V _{IN} = V _{IH} or V _{IL}	MIL, I _{OH} = -1.0mA	2.4	3.4		Volts
			COM'L, I _{OH} = -2.6mA	2.4	3.4		
V _{OL}	Output LOW Voltage	V _{CC} = MIN. V _{IN} = V _{IH} or V _{IL}	I _{OL} = 4.0mA			0.4	Volts
			I _{OL} = 8.0mA			0.45	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		MIL		0.7	Volts
				COM'L		0.8	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA				-1.5	Volts
I _{IL}	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.4V				-0.36	mA
I _{IH}	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V				20	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 7.0V				0.1	mA
I _O	Off-State (High-Impedance) Output Current	V _{CC} = MAX.		V _O = 0.4V		-20	μA
				V _O = 2.4V		20	
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.		-15		-85	mA
I _{CC}	Power Supply Current (Note 4)	V _{CC} = MAX.			24	37	mA

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. All outputs open, $\bar{E} = \text{GND}$, Di inputs = CLR = $\bar{OE} = 4.5\text{V}$. Apply momentary ground, then 4.5V to clock input.

3

Am25LS

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am25LS2520

SWITCHING CHARACTERISTICS

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description		Min.	Typ.	Max.	Units	Test Conditions
t _{PLH}	Clock to Y _i (OE LOW)			18	27	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}				24	36		
t _{PHL}	Clear to Y			22	35	ns	
t _s	Data (D _i)		10	3		ns	
t _h	Data (D _i)		10	3		ns	
t _s	Enable (E)	Active	15	10		ns	
		Inactive	20	12			
t _h	Enable (E)		0	0		ns	
t _s	Clear Recovery (In-Active) to Clock		11	7		ns	
t _{pw}	Clock	HIGH	20	14		ns	
		LOW	25	13			
t _{pw}	Clear		20	13		ns	
t _{ZH}	OE to Y _i			9	13	ns	
t _{ZL}				14	21		
t _{HZ}	OE to Y _i			20	30	ns	
t _{LZ}				24	36		
f _{max}	Maximum Clock Frequency (Note 1)			40		MHz	

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	Clock to Y _i (OE LOW)			33		39	C _L = 50pF R _L = 2.0kΩ
t _{PHL}				45		54	
t _{PHL}	Clear to Y			43		51	
t _s	Data (D _i)		12		15		
t _h	Data (D _i)		12		15		
t _s	Enable (E)	Active	17		20		
		Inactive	20		23		
t _h	Enable (E)		0		0		
t _s	Clear Recovery (In-Active) to Clock		13		15		
t _{pw}	Clock	HIGH	25		30		
		LOW	30		35		
t _{pw}	Clear		22		25		
t _{ZH}	OE to Y _i			19		25	
t _{ZL}				30		39	
t _{HZ}	OE to Y _i			35		40	
t _{LZ}				39		42	
f _{max}	Maximum Clock Frequency (Note 1)		25		20		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

DEFINITION OF FUNCTIONAL TERMS

- D_i** The D flip-flop data inputs.
- $\overline{\text{CLR}}$** When the clear input is LOW, the Q_i outputs are LOW, regardless of the other inputs. When the clear input is HIGH, data can be entered into the register.
- CP** Clock Pulse for the Register; enters data into the register on the LOW-to-HIGH transition.
- Y_i** The register three-state outputs.
- $\overline{\text{E}}$** Clock Enable, When the clock enable is LOW, data on the D_i input is transferred to the Q_i output on the LOW-to-HIGH clock transition. When the clock enable is HIGH, the Q_i outputs do not change state, regardless of the data or clock input transitions.
- $\overline{\text{OE}}$** Output Control. When the $\overline{\text{OE}}$ input is HIGH, the Y_i outputs are in the high impedance state. When the $\overline{\text{OE}}$ input is LOW, the TRUE register data is present at the Y_i outputs.

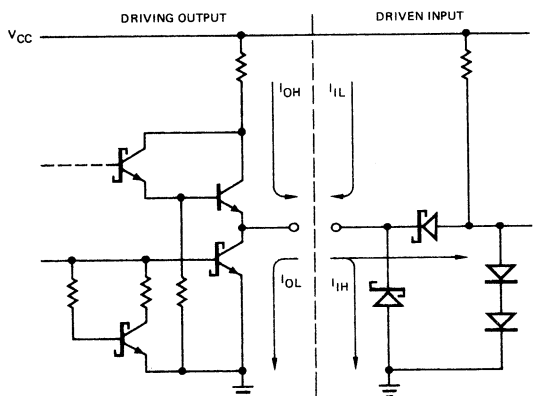
FUNCTION TABLE

Function	Inputs					Internal	Outputs
	$\overline{\text{OE}}$	$\overline{\text{CLR}}$	$\overline{\text{E}}$	D _i	CP		
Hi-Z	H	X	X	X	X	X	Z
Clear	H	L	X	X	X	L	Z
	L	L	X	X	X	L	L
Hold	H	H	H	X	X	NC	Z
	L	H	H	X	X	NC	NC
Load	H	H	L	L	↑	L	Z
	H	H	L	H	↑	H	Z
	L	H	L	L	↑	L	L
	L	H	L	H	↑	H	H

H = HIGH
 L = LOW
 X = Don't Care
 NC = No Change
 ↑ = LOW-to-HIGH Transition
 Z = High Impedance

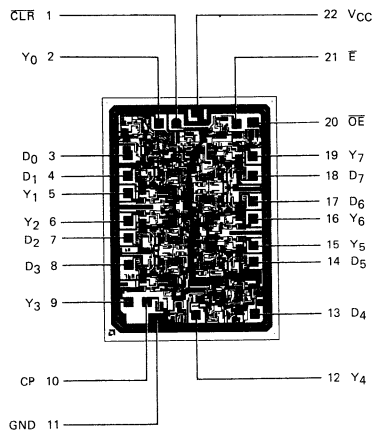
3

**Am25LS
 LOW-POWER SCHOTTKY INPUT/OUTPUT
 CURRENT INTERFACE CONDITIONS**



Note: Actual current flow direction shown.

Metallization and Pad Layout

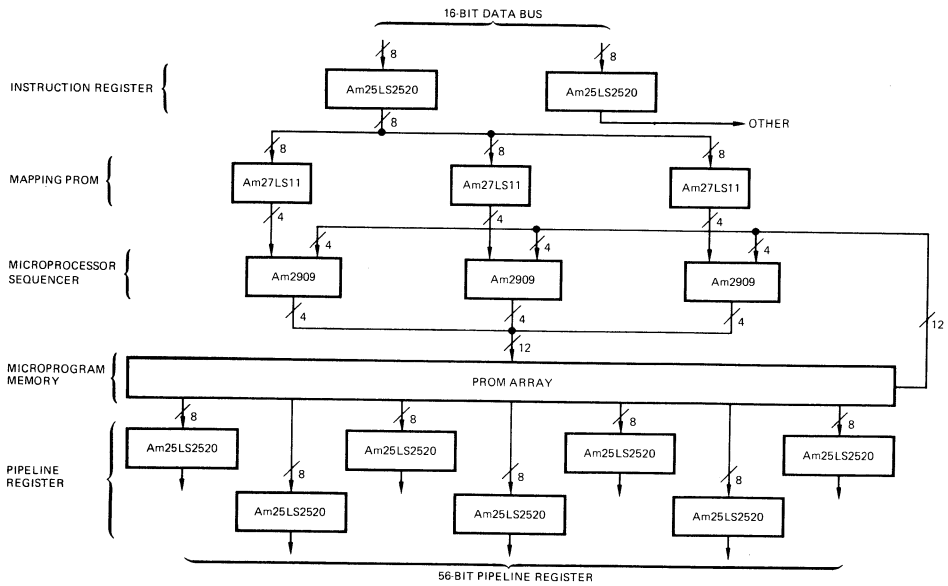


DIE SIZE 0.080" x 0.111"

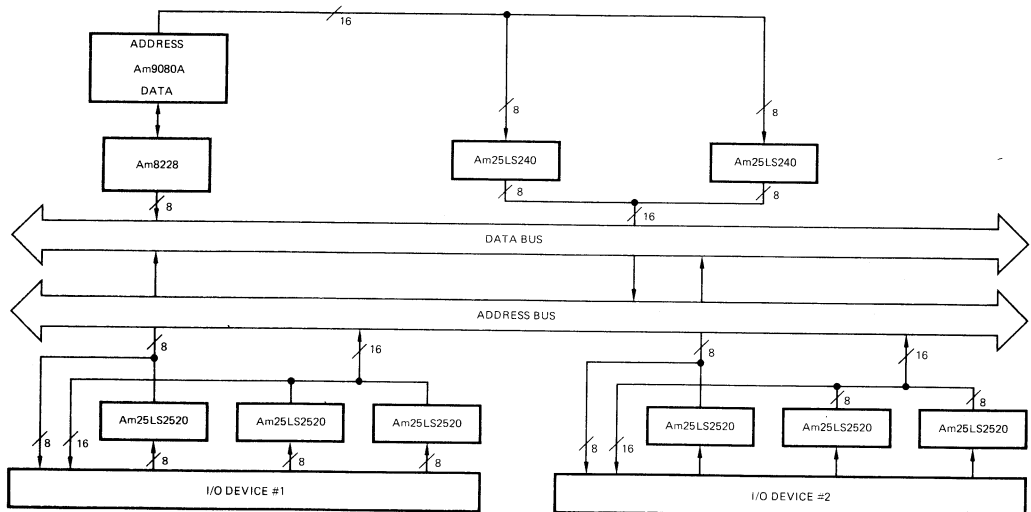
ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM25LS2520PC
Hermetic DIP	0°C to +70°C	AM25LS2520DC
Dice	0°C to +70°C	AM25LS2520XC
Hermetic DIP	-55°C to +125°C	AM25LS2520DM
Hermetic Flat Pak	-55°C to +125°C	AM25LS2520FM
Dice	-55°C to +125°C	AM25LS2520XM

APPLICATIONS



A typical Computer Control Unit for a microprogrammed machine.



The Am25LS2520 is a useful device in interfacing with the Am9080A system buses.

Am25LS2521

Eight-Bit Equal-To Comparator

DISTINCTIVE CHARACTERISTICS

- 8-bit byte oriented equal comparator
- Cascadable using \bar{E}_{IN}
- High-speed, Low-Power Schottky technology
- $t_{pd} A \bullet B$ to \bar{E}_{OUT} in 9ns
- Standard 20-pin package
- 100% product assurance screening to MIL-STD-883 requirements

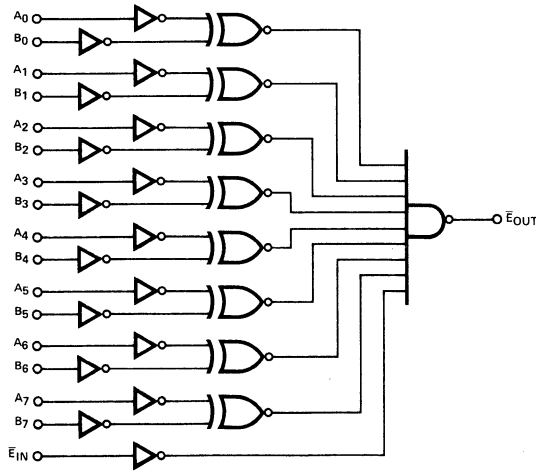
FUNCTIONAL DESCRIPTION

The Am25LS2521 is an 8-bit "equal to" comparator capable of comparing two 8-bit words for "equal to" with provision for expansion or external enabling. The matching of the two 8-bit inputs plus a logic LOW on the \bar{E}_{IN} produces an active LOW on the output \bar{E}_{OUT} .

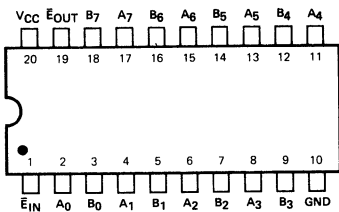
The logic expression for the device can be expressed as:

$$\bar{E}_{OUT} = (A_0 \odot B_0) (A_1 \odot B_1) (A_2 \odot B_2) (A_3 \odot B_3) (A_4 \odot B_4) (A_5 \odot B_5) (A_7 \odot B_7) \bar{E}_{IN}$$
 It is obvious that the expression is valid where $A_0 - A_7$ and $B_0 - B_7$ are expressed as either assertions or negations. This is also true for pair of terms i.e. A_0 can be compared with B_0 at the same time \bar{A}_1 is compared with \bar{B}_1 . It is only essential that the polarity of the paired terms be maintained.

LOGIC DIAGRAM

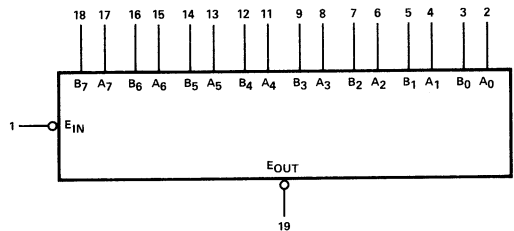


CONNECTION DIAGRAM



Note: Pin 1 is marked for orientation

LOGIC SYMBOL



V_{CC} = Pin 20
 GND = Pin 10

3

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25VMIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V**DC CHARACTERISTICS OVER OPERATING RANGE**

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -440\mu\text{A}$	MIL	2.5		Volts
				COM'L	2.7		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$			0.4	Volts
			$I_{OL} = 8.0\text{mA}$			0.45	
			$I_{OL} = 12\text{mA}$			0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0		Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		MIL		0.7	Volts
				COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$		A_i, B_i		-0.36	mA
				\bar{E}		-0.72	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$		A_i, B_i		20	μA
				\bar{E}		40	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{V}$		A_i, B_i		0.1	mA
				\bar{E}		0.2	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$			27	40	mA

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. $\bar{E} = \text{GND}$, all other inputs and outputs open.**MAXIMUM RATINGS** (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

SWITCHING CHARACTERISTICS

 $(T_A = +25^\circ\text{C}, V_{CC} = 5.0\text{V})$

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	A_i or B_i to $\overline{\text{Equal}}$		9	15	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			9	15		
t_{PLH}	\overline{E} to $\overline{\text{Equal}}$		5	7	ns	
t_{PHL}			6	8		

SWITCHING CHARACTERISTICS
OVER OPERATING RANGE *

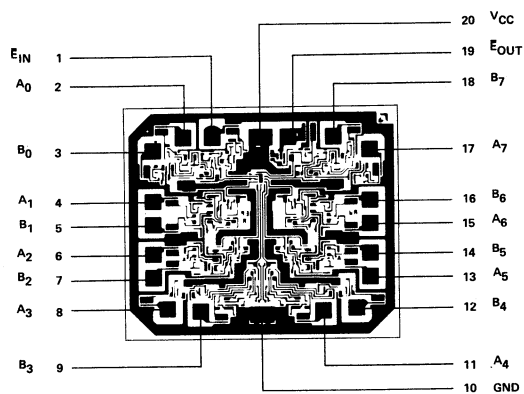
Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	A_i or B_i to $\overline{\text{Equal}}$ Output		20		22	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			19		21		
t_{PLH}	\overline{E} to $\overline{\text{Equal}}$ Output		10.5		12	ns	
t_{PHL}			12.5		15		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

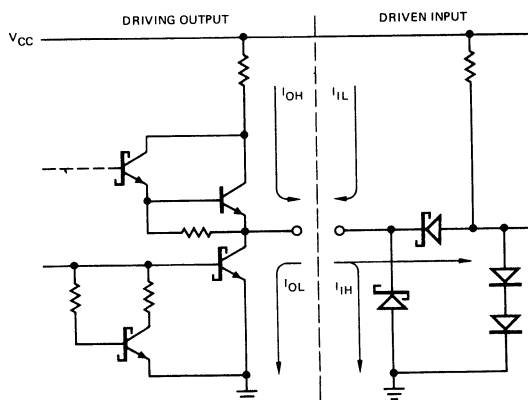
DEFINITION OF FUNCTIONAL TERMS

A_0 – A_7 A input to comparator
 B_0 – B_7 B input to comparator
 \overline{E}_{IN} Enable active LOW
 \overline{E}_{OUT} $\overline{\text{EQUAL}}$ output active LOW

Metallization and Pad Layout

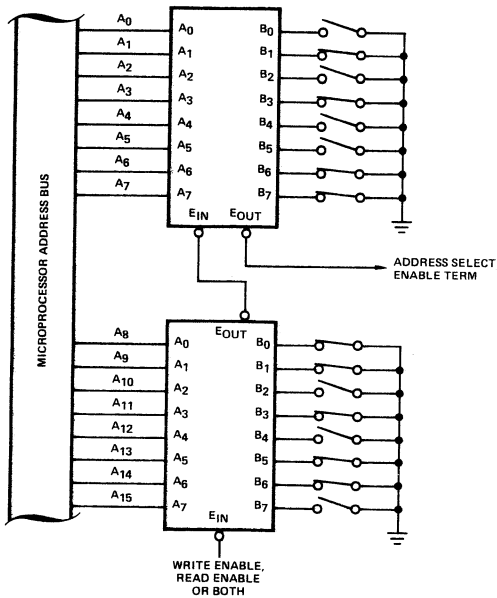


DIE SIZE 0.063" x 0.074"

Am25LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS

Note: Actual current flow direction shown.

APPLICATION



MAX. ENABLE (HIGH-to-LOW) DELAY
OVER 16-BITS
(Commercial Range)

t_{PHL}	A_i or B_i to \overline{E}_{OUT}	19ns
t_{PHL}	\overline{E}_{IN} to \overline{E}_{OUT}	12.5ns
Total		31.5ns

MICROPROCESSOR ENABLE CONTROLLED,
SELECTABLE, ADDRESS DECODER

ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM25LS2521PC
Hermetic DIP	0°C to +70°C	AM25LS2521DC
Dice	0°C to +70°C	AM25LS2521XC
Hermetic DIP	-55°C to +125°C	AM25LS2521DM
Hermetic Flat Pak	-55°C to +125°C	AM25LS2521FM
Dice	-55°C to +125°C	AM25LS2521XM

Am25LS2524

Registered Comparator

DISTINCTIVE CHARACTERISTICS

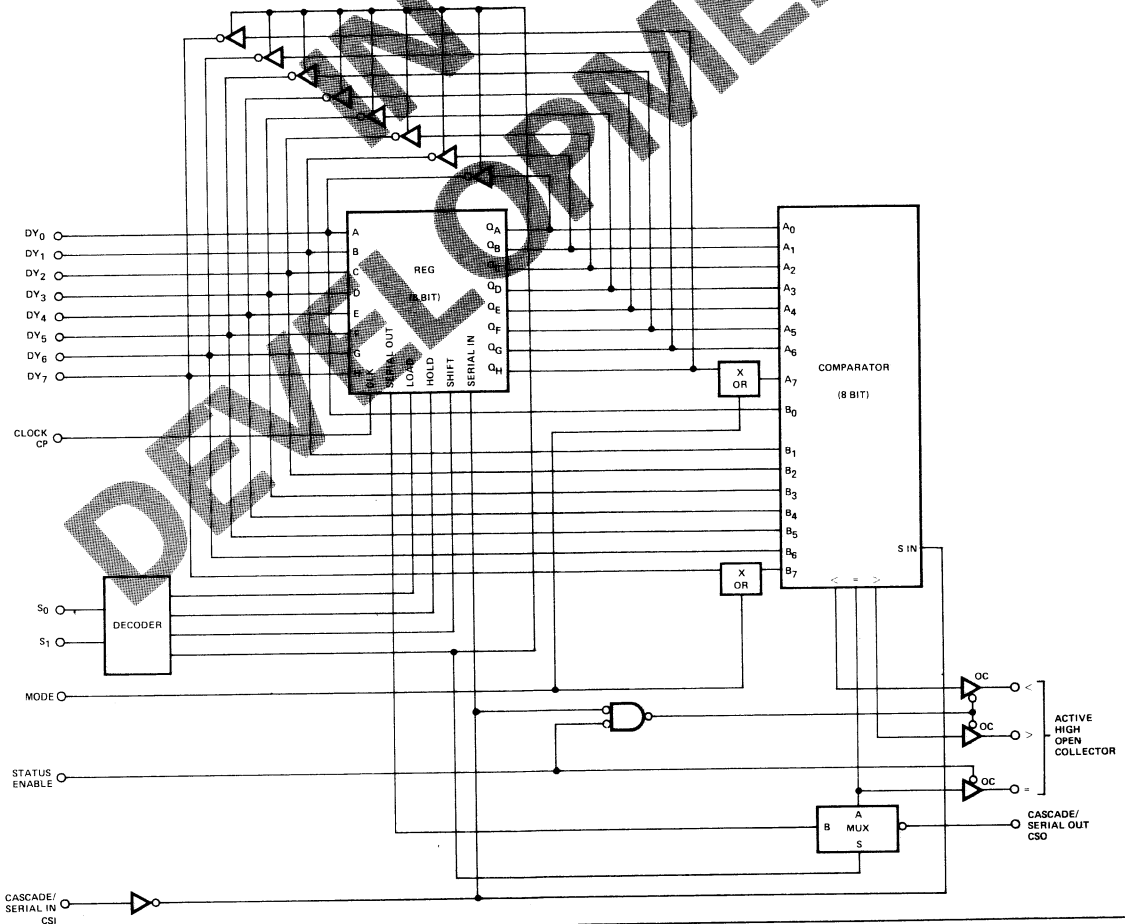
- Eight-bit bi-directional register with bus oriented input-output
- Independent serial input-output to register
- Register to bus comparator with equal to greater than and less than outputs
- Cascadable in groups of eight bits
- Comparator has open collector status outputs controlled by status enable
- Compare performed at 2's complement or magnitude
- Controlled by 2-bit function code
- Standard 20-pin package
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am25LS2524 is an eight-bit bi-directional register with parallel input and output plus serial input and output progressing from LSB to MSB. Also attached to the input/output is an eight-bit comparator with one port tied to the register output and the other port tied to the input/output pins. The device outputs are three open collector, active HIGH outputs representing "equal to", "greater than", "less than". Provision has been made to disable these outputs (to OFF state) by the use of Status Enable. The device functions are controlled by two control lines, S_0S_1 , to execute shift, load, hold, and readout.

A mode control has been provided to allow two's complement as well as magnitude compare. All data inputs, serial and parallel, are loaded by the rising edge of the input clock. An output is also provided for cascading the device to accommodate wider bit fields in groups of eight bits per device.

LOGIC DIAGRAM
8-Bit Registered Comparator



Am25LS2525

System Clock Generator and Driver

DISTINCTIVE CHARACTERISTICS

- Single chip clock generator and driver
- Five different clock output waveforms for Am2900 and other bipolar and MOS systems
- Crystal controlled for stable system operation
- Oscillator to 33MHz – oscillator output for external system timing
- Clock halt, single-step and wait controls
- Variable cycle lengths – 1-of-8 different cycle lengths may be programmed
- 20-Pin package
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

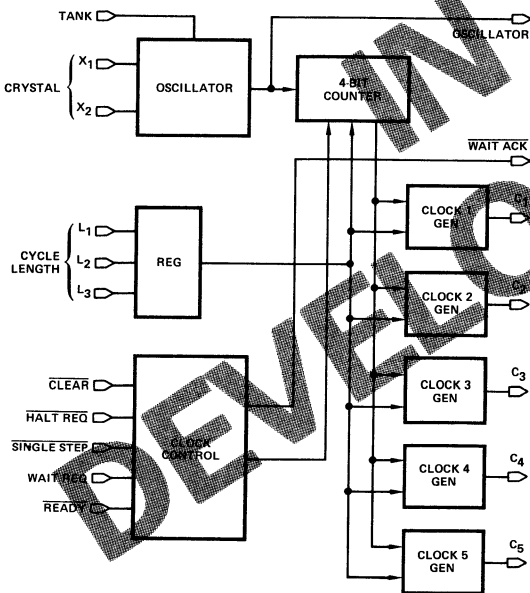
The Am25LS2525 is a single-chip general purpose clock generator/driver. It is controlled by a crystal, selected by the designer, and is microprogrammable to meet a variety of system speed requirements. The Am25LS2525 generates five different clock output waveforms tailored to meet the needs of Am2900 and other bipolar and MOS microprocessor based systems. Also, variable cycle lengths may be generated under microprogram control. One-of-eight different cycle lengths may be microprogrammed using the Cycle Length inputs L1, L2, and L3.

The Am25LS2525 oscillator runs at frequencies up to 33 MHz. An input pin is provided for a tank circuit which allows the use of overtone mode crystals. A buffered oscillator output is provided for external system timing.

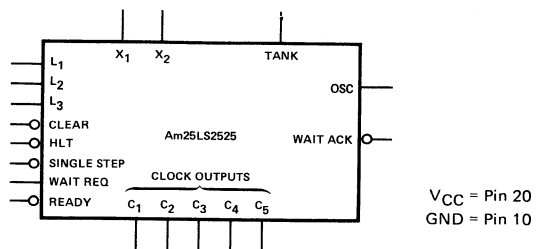
Clock halt, single-step and wait controls are provided for the Am25LS2525. The HALT REQ input halts the clocks; the clocks resume when the HALT REQ input is deactivated. The SINGLE-STEP input, which operates only when the clocks are halted, generates the clocks for a single cycle. The WAIT REQ input stops the clocks and puts the Am25LS2525 in a "wait" state. In this state, the clocks remain stopped until an asynchronous READY input signal is received. The WAIT ACK output indicates when the Am25LS2525 is in the "wait" state. The WAIT REQ and READY inputs are pulse sensitive and are overridden by the HALT REQ input.

One-of-eight cycle lengths may be microprogrammed using the L1, L2, and L3 inputs. There are five clock output waveforms for each of the eight possible cycle lengths.

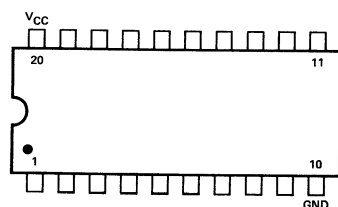
LOGIC DIAGRAM



LOGIC SYMBOL



CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

Am25LS2535

Eight Input Multiplexer With Control Register

DISTINCTIVE CHARACTERISTICS

- High speed eight-input multiplexer
- On-chip Multiplexer Select and Polarity Control Register
- Output polarity control for inverting or non-inverting output
- Common register enable
- Asynchronous register clear
- Three-state output for expansion
- Am25LS features improved noise margin, higher drive, and faster operation
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am25LS2535 is an eight-input Multiplexer with Control Register. The device features high speed from clock to output and is intended for use in high speed computer control units or structured state machine designs.

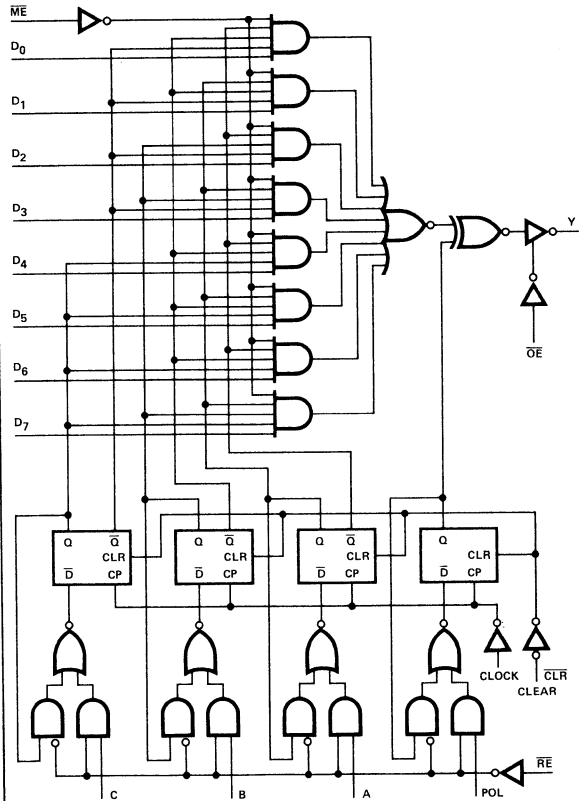
The Am25LS2535 contains an internal register which holds the A, B and C multiplexer select lines as well as the POL (polarity) control bit. When the Register Enable input (\overline{RE}) is LOW, new data is entered into the register on the LOW-to-HIGH transition of the clock. When \overline{RE} is HIGH, the register retains its current data. An asynchronous clear input (CLR) is used to reset the register to a logic LOW level.

The A, B and C register outputs select one of eight multiplexer data inputs. A HIGH on the Polarity Control flip-flop output causes a true (non-inverting) multiplexer output, and a LOW causes the output to be inverted. In a computer control unit, this allows testing of either true or complemented flag data at the microprogram sequencer test input.

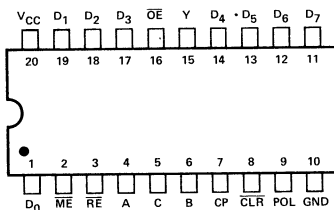
An active LOW Multiplexer Enable input (\overline{ME}) allows the selected multiplexer input to be passed to the output. When \overline{ME} is HIGH, the output is determined only by the Polarity Control bit.

The Am25LS2535 also features a three-state Output Enable control (\overline{OE}) for expansion. When \overline{OE} is LOW, the output is enabled. When \overline{OE} is HIGH, the output is in the high impedance state.

LOGIC DIAGRAM

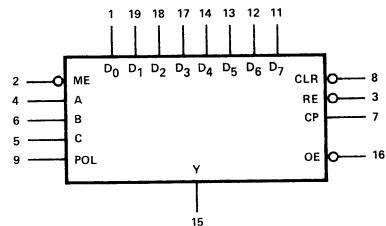


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 20
GND = Pin 10

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\%$	MIN. = 4.75 V	MAX. = 5.25 V
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\%$	MIN. = 4.50 V	MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL, $I_{OH} = -2.0\text{mA}$ COM'L, $I_{OH} = -6.5\text{mA}$	2.4	3.4		Volts
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$ $I_{OL} = 8.0\text{mA}$ $I_{OL} = 20\text{mA}$			0.4 0.45 0.5	Volts
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		MIL COM'L		0.7 0.8	Volts
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.},$ $V_{IN} = 0.4\text{V}$	$\overline{ME}, \overline{OE}, \overline{RE}$ $D_N, A, B, C, \text{POL}, CP, \overline{CLR}$			-0.72 -2.0	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.},$ $V_{IN} = 2.7\text{V}$	$\overline{ME}, \overline{OE}, \overline{RE}$ $D_N, A, B, C, \text{POL}, CP, \overline{CLR}$			40 50	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.},$ $V_{IN} = 5.5\text{V}$	$\overline{ME}, \overline{OE}, \overline{RE}$ $D_N, A, B, C, \text{POL}, CP, \overline{CLR}$			0.1 1.0	mA
I_{OZ}	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$ $V_O = 2.4\text{V}$			-50 50	μA
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-40		-100	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$			97	148	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. $D_1 - D_7, A, B, C, \text{POL}, \overline{ME}, \overline{CLR}$ at GND. All other inputs and outputs open.
 Measured after a momentary ground then 4.5V applied to clock input.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	$-65^\circ\text{C to } +150^\circ\text{C}$
Temperature (Ambient) Under Bias	$-55^\circ\text{C to } +125^\circ\text{C}$
Supply Voltage to Ground Potential Continuous	$-0.5\text{V to } +7.0\text{V}$
DC Voltage Applied to Outputs for High Output State	$-0.5\text{V to } +V_{CC} \text{ max.}$
DC Input Voltage	$-0.5\text{V to } +5.5\text{V}$
DC Output Current, Into Outputs	30mA
DC Input Current	$-30\text{mA to } +5.0\text{mA}$

SWITCHING CHARACTERISTICS

 $(T_A = +25^\circ\text{C}, V_{CC} = 5.0\text{V})$

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	Clock to Y POL – LOW		21	32	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			19	29		
t_{PLH}	Clock to Y POL – HIGH		16	24	ns	
t_{PHL}			19	29		
t_{PLH}	D_n to Y		10	16	ns	
t_{PHL}			13	19		
t_{PLH}	$\overline{\text{CLR}}$ to Y		22	33	ns	
t_{PHL}			22	33		
t_{PLH}	$\overline{\text{ME}}$ to Y		12	18	ns	
t_{PHL}			12	18		
t_{ZL}	$\overline{\text{OE}}$ to Y		8	14	ns	
t_{ZH}			8	14		
t_{LZ}			10	17	ns	
t_{HZ}			10	17		
t_s	A, B, C, POL	10			ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
	$\overline{\text{RE}}$	15				
t_s	$\overline{\text{CLR}}$ Recovery	5			ns	
t_{pw}	Clock	10			ns	
	$\overline{\text{Clear}}$ (LOW)	10				
t_H	A, B, C, POL, $\overline{\text{RE}}$	0			ns	

SWITCHING CHARACTERISTICS
OVER OPERATING RANGE*

Am25LS COM'L		Am25LS MIL	
$T_A = 0^\circ\text{C to } +70^\circ\text{C}$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	
$V_{CC} = 5.0\text{V} \pm 5\%$		$V_{CC} = 5.0\text{V} \pm 10\%$	
Min.	Max.	Min.	Max.

Parameters	Description	Min.	Max.	Min.	Max.	Units	Test Conditions
t_{PLH}	Clock to Y, POL-L		40		47	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			34		38		
t_{PLH}	Clock to Y, POL-H		29		33	ns	
t_{PHL}			35		41		
t_{PLH}	D_N to Y		19		21	ns	
t_{PHL}			22		24		
t_{PLH}	$\overline{\text{CLR}}$ to Y		39		45	ns	
t_{PHL}			39		45		
t_{PLH}	$\overline{\text{ME}}$ to Y		22		26	ns	
t_{PHL}			19		20		
t_{ZL}	$\overline{\text{OE}}$ to Y		19		24	ns	
t_{ZH}			22		29		
t_{LZ}	OE to Y		24		30	ns	
t_{HZ}			24		30		
t_s	A, B, C POL	11		12	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$	
	$\overline{\text{RE}}$	18		20			
t_s	$\overline{\text{CLR}}$ Recovery	6		7	ns		
t_{pw}	Clock	11		12	ns		
	Clear (LOW)	11		12			
t_H	A, B, C, POL, $\overline{\text{RE}}$	3		3	ns		

* AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

3

FUNCTION TABLE

MODE	INPUTS							INTERNAL				INPUTS		OUTPUT
	C	B	A	POL	\overline{RE}	\overline{CLR}	CP	Q_C	Q_B	Q_A	Q_{POL}	\overline{ME}	\overline{OE}	Y
Clear	X	X	X	X	X	L	X	L	L	L	L	H	L	H
	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	L	L	$\overline{D_0}$
Reg. Disable	X	X	X	X	H	H	X	NC	NC	NC	NC	L	L	D_i/D_i (Note 1)
Select (Multiplex)	L	L	L	L/H	L	H	↑	L	L	L	L/H	L	L	$\overline{D_0}/D_0$
	L	L	H	↓	↓	↓	↓	L	L	H	↓	↓	↓	$\overline{D_1}/D_1$
	L	H	L	↓	↓	↓	↓	L	H	L	↓	↓	↓	$\overline{D_2}/D_2$
	L	H	H	↓	↓	↓	↓	L	H	H	↓	↓	↓	$\overline{D_3}/D_3$
	H	L	L	↓	↓	↓	↓	H	L	L	↓	↓	↓	$\overline{D_4}/D_4$
	H	L	H	↓	↓	↓	↓	H	L	H	↓	↓	↓	$\overline{D_5}/D_5$
	H	H	L	↓	↓	↓	↓	H	H	L	↓	↓	↓	$\overline{D_6}/D_6$
	H	H	H	↓	↓	↓	↓	H	H	H	↓	↓	↓	$\overline{D_7}/D_7$
Multiplexer Disable	X	X	X	X	X	H	X	X	X	X	L	H	L	H
	↓	↓	↓	↓	↓	↓	↓	X	X	X	H	H	L	L
Tri-state Output Disable	↓	↓	↓	↓	↓	↓	↓	X	X	X	X	X	H	Z

NC = No Change

X = Don't Care

Note 1: The output will follow the selected input, D_i , or its complement depending on the state of the POL flip-flop.

DEFINITION OF FUNCTIONAL TERMS

A, B, C Multiplexer Select Lines. One of eight multiplexer data inputs is selected by the A, B and C register outputs.

POL Polarity Control Bit. A HIGH register output causes a true (non-inverted) output and a LOW causes the output to be inverted.

\overline{ME} Multiplexer Enable. When LOW, it enabled the 8-input multiplexer. When HIGH, the Y output is determined by only the Polarity Control bit.

\overline{RE} Register Enable. When LOW, the Multiplexer Select and Polarity Control Register is enabled for loading. When HIGH, the register holds its current data.

\overline{CLR} Clear. A LOW asynchronously resets the Multiplexer Select and Polarity Control Register.

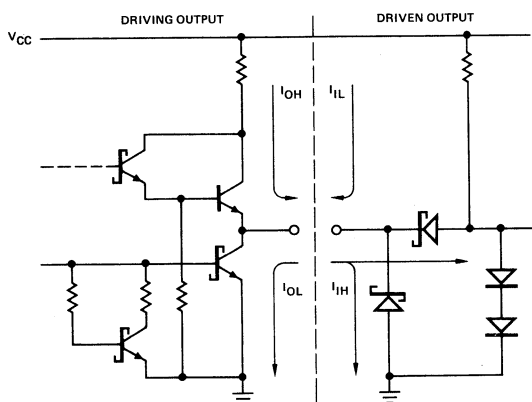
D_1 - D_8 Data Inputs to the 8-input multiplexer.

CP Clock Pulse. When \overline{RE} is LOW, the Multiplexer Select and Polarity Control Register changes state on the LOW-to-HIGH transition of CP.

\overline{OE} Output Enable. When LOW, the output is enabled. When HIGH, the output is in the high impedance state.

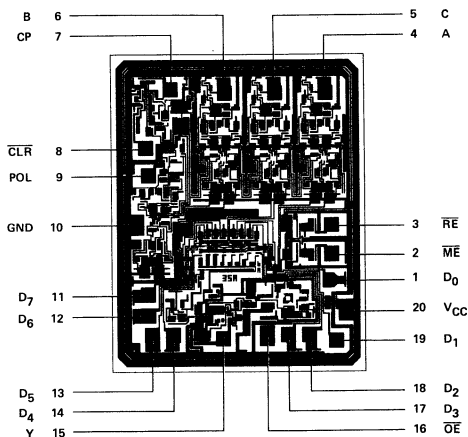
Y The chip output.

Am25LS LOW-POWER SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



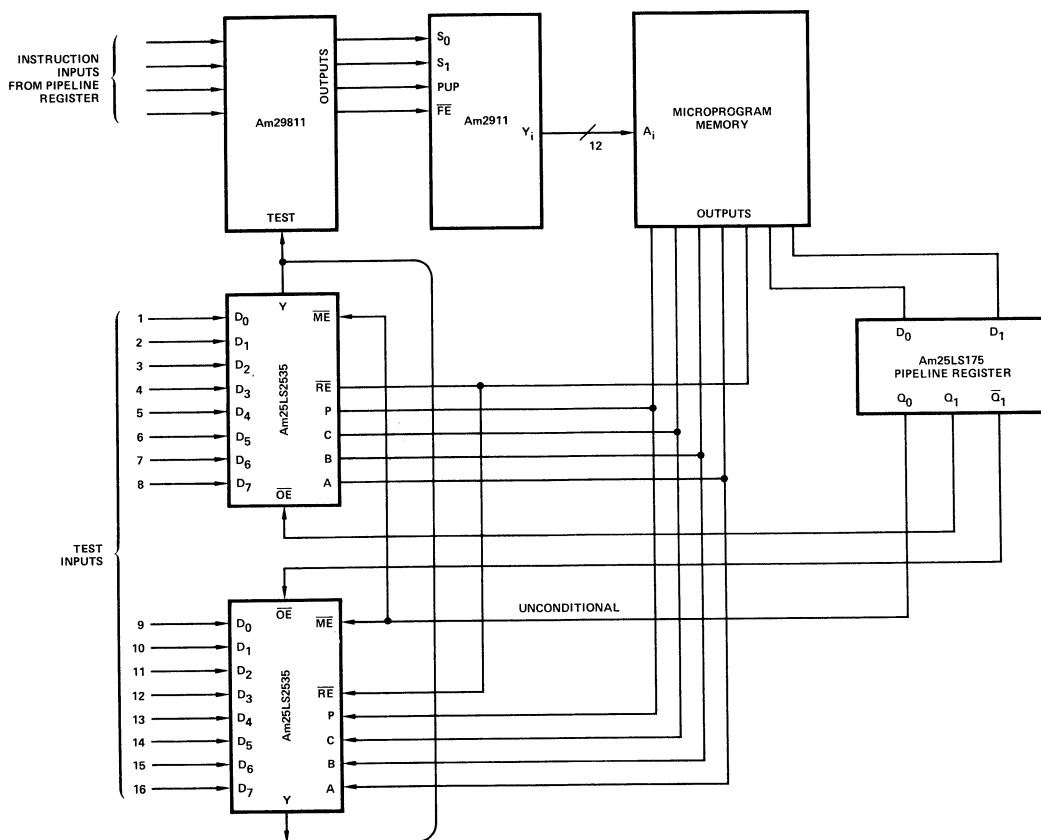
Note: Actual current flow direction shown.

Metallization and Pad Layout



DIE SIZE 0.080" X 0.099"

APPLICATION



A versatile one-of-sixteen Test Select with Polarity Control and Test Select Hold.

3

Am25LS2536

Eight-Bit Decoder With Control Storage

DISTINCTIVE CHARACTERISTICS

- 8-bit decoder/demultiplexer with control storage
- 3-state outputs
- Common clock enable
- Common clear
- Polarity control
- Advanced Low Power Schottky Process
- 100% product assurance screening to MIL-STD-883 requirements

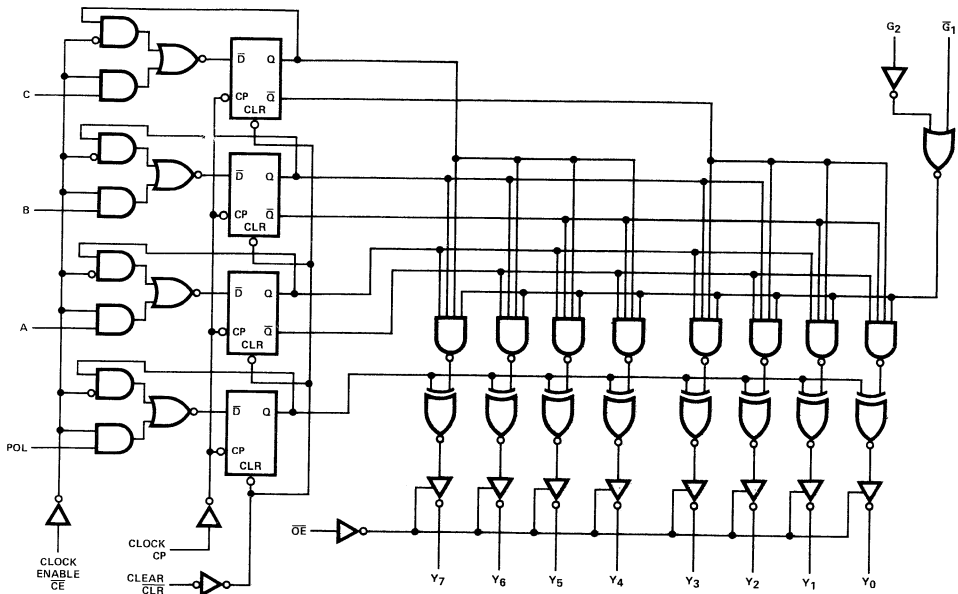
FUNCTIONAL DESCRIPTION

The Am25LS2536 is an eight-bit decoder with control storage. It provides a conventional 8-bit decoder function with two enable inputs which may also be used for data input. This can be used to implement a demultiplexer function. In addition, the exclusive "OR" gate allows for polarity control of the selected output. The 3-state outputs are enabled by a LOW on the (OE) output enable.

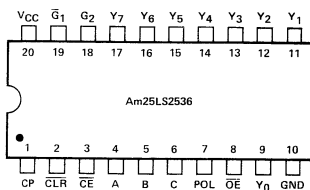
The three control bits representing the output selection and the single bit polarity control are stored in "D" type flip-flops. These flip-flops have both Clear, Clock, and Clock Enable functions provided. The G_1 and \overline{G}_2 input provide either polarity for input control or data.

LOGIC DIAGRAM

8-Bit Decoder/Demultiplexer with Control Storage

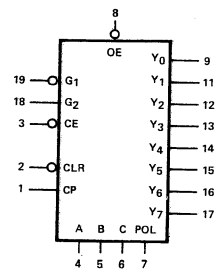


CONNECTION DIAGRAM



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



$V_{CC} = 20$
 $GND = 10$

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 V
 MIL $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -2.6\text{mA}$, COM'L	2.4	3.2	Volts	
			$I_{OH} = -1.0\text{mA}$, MIL	2.4	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 24\text{mA}$, COM'L		0.4	0.5	Volts
			$I_{OL} = 12\text{mA}$, MIL		0.35	0.4	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0		Volts	
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts	
			COM'L		0.8		
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$			-1.5	Volts	
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$			-0.4	mA	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$			20	μA	
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 7.0\text{V}$			0.1	mA	
I_O	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$		-20	μA	
			$V_O = 2.4\text{V}$		20		
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15	-85	mA	
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$			37	56	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Test Conditions: $A = B = C = \overline{G}_1 = G_2 = \overline{OE} = \overline{CE} = \text{GND}$; $\text{CLK} = \text{CLR} = \text{POL} = 4.5\text{V}$.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to $+150^\circ\text{C}$
Temperature (Ambient) Under Bias	-55°C to $+125^\circ\text{C}$
Supply Voltage to Ground Potential Continuous	-0.5V to $+7.0\text{V}$
DC Voltage Applied to Outputs for High Output State	-0.5V to $+V_{CC}$ max.
DC Input Voltage	-0.5V to $+7.0\text{V}$
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to $+5.0\text{mA}$

SWITCHING CHARACTERISTICS $(T_A = +25^\circ\text{C}, V_{CC} = 5.0\text{V})$

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	G ₁ to Y ₀ - Y ₇		17	25	ns	C _L = 45pF R _L = 667Ω
t_{PHL}			23	34		
t_{PLH}	G ₂ to Y ₀ - Y ₇		20	30	ns	
t_{PHL}			26	39		
t_{PLH}	CP to Y ₀ - Y ₇		24	36	ns	
t_{PHL}			30	45		
t_{PLH}	CLR to Y ₀ - Y ₇		24	36	ns	
t_{PHL}			31	46		
t_s	Clock Enable to CP	25			ns	
t_h		0				
t_s	A, B, C, POL to CP	15			ns	
t_h		0				
t_{HZ}	OE to Y ₀ - Y ₇		9	14	ns	C _L = 45pF R _L = 667Ω
t_{LZ}			11	17		
t_{ZH}	OE to Y ₀ - Y ₇		15	22	ns	C _L = 45pF R _L = 667Ω
t_{ZL}			16	24		
t_s	Set-up Time, Clear Recovery to CP	20			ns	
t_{pw}	Pulse Width	Clock	15		ns	
		Clear	15			

**SWITCHING CHARACTERISTICS
OVER OPERATING RANGE***

Parameters	Description	Am26LS COM'L		Am25LS MIL		Units	Test Conditions
		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$			
		Min.	Max.	Min.	Max.		
t_{PLH}	G ₁ to Y ₀ - Y ₇		29		31	ns	C _L = 45pF R _L = 667Ω
t_{PHL}			39		42		
t_{PLH}	G ₂ to Y ₀ - Y ₇		34		37	ns	
t_{PHL}			44		48		
t_{PLH}	CP to Y ₀ - Y ₇		40		42	ns	
t_{PHL}			51		55		
t_{PLH}	CLR to Y ₀ - Y ₇		47		54	ns	
t_{PHL}			58		66		
t_s	Clock Enable to CP	27		30		ns	
t_h		0		0			
t_s	A, B, C, POL to CP	17		20		ns	
t_h		0		0			
t_{HZ}	OE to Y ₀ - Y ₇		17		18	ns	C _L = 5.0pF R _L = 667Ω
t_{LZ}				27			
t_{ZH}	OE to Y ₀ - Y ₇		25		27	ns	C _L = 5.0pF R _L = 667Ω
t_{ZL}				28			
t_s	Set-up Time, Clear Recovery to CP	23		25		ns	
t_{pw}	Pulse Width	Clock	17		20	ns	
		Clear	15		15		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

FUNCTION TABLE

Mode	Inputs								Internal Registers				Three-State Outputs								
	C	B	A	POL	\overline{CE}	\overline{CLR}	G*	\overline{OE}	CP	QC	QB	QA	QPOL	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7
Clear	X	X	X	X	X	L	L	L	X	L	L	L	L	H	H	H	H	H	H	H	H
	X	X	X	X	X	L	L	L	X	L	L	L	L	L	H	H	H	H	H	H	H
Hold	X	X	X	X	H	H	NC	L	↑	NC	NC	NC	NC	NC	NC	NC	NC	NC	NC	NC	NC
Select	L	L	L	H	L	H	H	L	↑	L	L	L	H	H	L	L	L	L	L	L	L
	L	L	H	H	L	H	H	L	↑	L	L	H	H	L	H	L	L	L	L	L	L
	L	H	L	H	L	H	H	L	↑	L	H	L	H	L	L	H	L	L	L	L	L
	L	H	H	H	L	H	H	L	↑	L	H	H	H	L	L	L	H	L	L	L	L
	H	L	L	H	L	H	H	L	↑	H	L	L	H	L	L	L	L	H	L	L	L
	H	L	H	H	L	H	H	L	↑	H	L	H	H	L	L	L	L	L	H	L	L
	H	H	L	H	L	H	H	L	↑	H	H	L	H	L	L	L	L	L	L	H	L
	H	H	H	H	L	H	H	L	↑	H	H	H	H	L	L	L	L	L	L	L	H
	L	L	L	L	L	H	H	L	↑	L	L	L	L	L	H	H	H	H	H	H	H
	L	L	H	L	L	H	H	L	↑	L	L	H	L	H	L	H	H	H	H	H	H
	L	H	L	L	L	H	H	L	↑	L	H	L	L	H	H	L	H	H	H	H	H
	H	L	L	L	L	H	H	L	↑	H	L	L	L	H	H	H	L	H	H	H	H
	H	L	H	L	L	H	H	L	↑	H	L	H	L	H	H	H	H	L	H	L	H
	H	H	L	L	L	H	H	L	↑	H	H	L	L	H	H	H	H	H	H	L	H
	H	H	H	L	L	H	H	L	↑	X	H	H	L	H	H	H	H	H	H	H	L
	X	X	X	H	L	H	L	L	↑	X	X	X	H	L	L	L	L	L	L	L	L
X	X	X	L	L	H	L	L	↑	X	X	X	L	H	H	H	H	H	H	H	H	
Output Disable	X	X	X	X	X	X	X	H	X	NC	NC	NC	NC	Z	Z	Z	Z	Z	Z	Z	Z

\overline{G}_1	G_2	G
L	L	L
L	H	H
H	L	L
H	H	L

NC = No Change X = Don't Care Z = High-Impedance ↑ = Low-to-High Transition

DEFINITION OF TERMS

\overline{CLR} CLEAR – When the CLEAR input is LOW, the control register outputs (Q_A , Q_B , Q_C , Q_{POL}) are set LOW regardless of any other inputs.

CP CLOCK – Enters data into the control register on the LOW-to-HIGH transition.

\overline{CE} CLOCK ENABLE – Allows data to enter the control register when \overline{CE} is LOW. When \overline{CE} is HIGH, the Q_i outputs do not change state, regardless of data or clock input transitions.

A, B, C Inputs to the control register which are entered on the LOW-to-HIGH clock transition if \overline{CE} is LOW.

POL Input to the control register bit used for determining the polarity of the selected output.

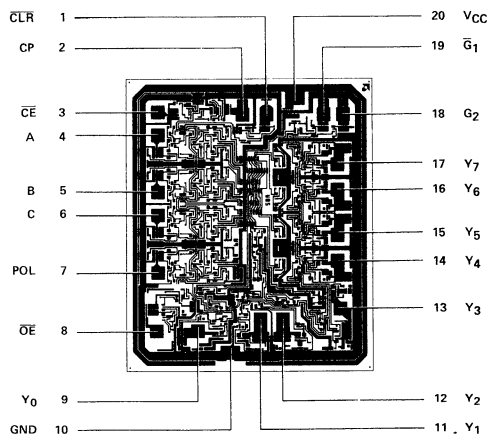
\overline{G}_1 Active LOW part of the expression $G = G_1 G_2$ [or $G = (\overline{G}_1) G_2$] where G is either data input for the selected Y_n or is used as an input enable.

G_2 Active HIGH part of the expression $G = G_1 G_2$.

Y_n The three-state outputs. When active ($\overline{OE} = \text{LOW}$), one of eight outputs is selected by the code stored in the control register, with the polarity of all eight determined by the bit stored in the POL flip-flop of the control register. The selected output can further be controlled by \overline{G} according to the expression $Y_{\text{SELECTED}} = \overline{G} \oplus Q_{\text{POL}}$.

\overline{OE} OUTPUT ENABLE. When \overline{OE} is HIGH the Y_n outputs are in the high impedance state; when \overline{OE} is LOW the Y_n 's are in their active state as determined by the other control logic. The \overline{OE} input affects the Y_n output buffers only and has no effect on the control register or any other logic.

Metallization and Pad Layout



DIE SIZE 0.084" X 0.099"

Am25LS2537

One-Of-Ten Decoder With Three-State Outputs And Polarity Control

DISTINCTIVE CHARACTERISTICS

- Three-state outputs
- Separate output polarity control
- Inverting and non-inverting enable inputs
- Does not respond to codes above nine
- A.C. parameters specified over operating temperature and power supply ranges
- 100% product assurance screening to MIL-STD-883 requirements

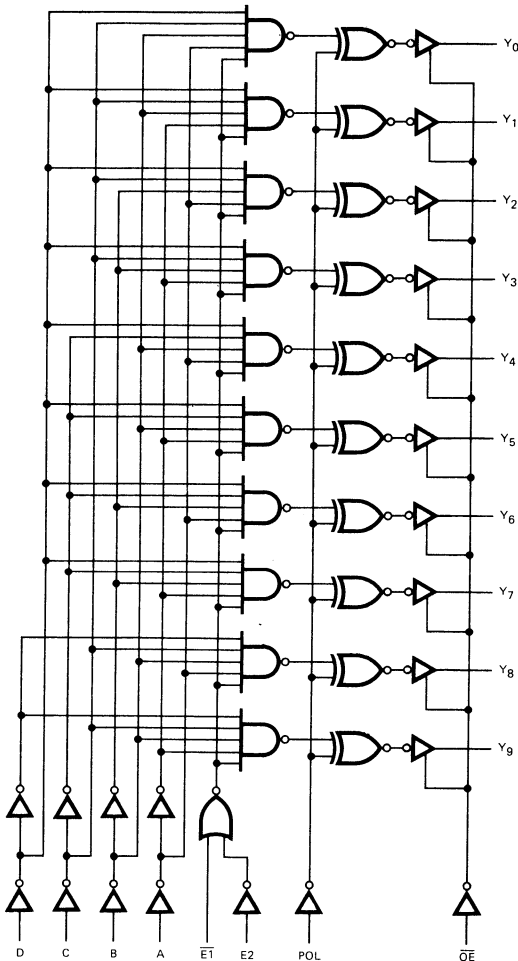
FUNCTIONAL DESCRIPTION

The Am25LS2537 is a demultiplexer/one-of-ten decoder that accepts four active high BCD inputs and selects one-of-ten mutually exclusive outputs. The device features three-state outputs as well as a buffered common polarity control such that the outputs are mutually exclusive active-low or mutually exclusive active-high. The logic design of the Am25LS2537 ensures that all outputs are unselected when the binary codes greater than nine are applied to the inputs. The inputs A, B, C, and D of the Am25LS2537 correspond to the respective binary weight of 1, 2, 4, and 8.

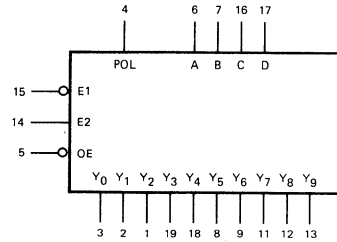
The output enable (\overline{OE}) input controls the three-state outputs. When the \overline{OE} input is **HIGH**, the outputs are in the high impedance state. When the \overline{OE} input is **LOW**, the outputs are enabled. The polarity (POL) input is used to drive the Y outputs to either the active-HIGH state or the active-LOW state. When the POL input is **LOW**, the outputs are active-HIGH. When the POL input is **HIGH**, the Y outputs are active-LOW. The device features one active-HIGH and one active-LOW enable input which can be used for gating the decoder or can be used with incoming data for demultiplexing applications.

The Am25LS2537 is packaged in a space saving (0.3-inch row spacing) 20-pin package. The device also features Am25LS family faster switching specifications, higher noise margin, and twice the fan-out over the military temperature range when compared with Am54LS/74LS devices.

LOGIC DIAGRAM

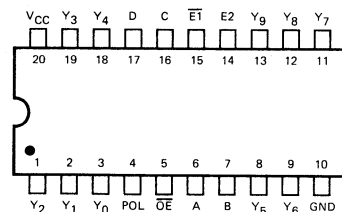


LOGIC SYMBOL



V_{CC} = Pin 20
GND = Pin 10

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L = $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75 V MAX. = 5.25 V
MIL = $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50 V MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	MIL, $I_{OH} = -1.0\text{mA}$	2.4	3.4		Volts
			COM'L, $I_{OH} = -2.6\text{mA}$	2.4	3.4		
V_{OL}	Output LOW Voltage (Note 5)	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4.0\text{mA}$			0.4	Volts
			$I_{OL} = 8.0\text{mA}$			0.45	
			$I_{OL} = 12\text{mA}$			0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$				-0.36	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$				20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 7.0\text{V}$				0.1	mA
I_{OZ}	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$			-20	μA
			$V_O = 2.4\text{V}$			20	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$			25	40	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
4. Test conditions: A = B = C = D = E1 = GND; E2 = POL = $\overline{OE} = 4.5\text{V}$.
5. V_{OL} is specified with total device $I_{OL} = 60\text{mA}$ (max.).

3**MAXIMUM RATINGS** (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

Am25LS2537

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t _{PLH}	A, B, C, D to Y _i		22	33	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			17	25		
t _{PLH}	E ₁ to Y _i		19	28	ns	
t _{PHL}			21	31		
t _{PLH}	\overline{E}_2 to Y _i		21	31	ns	
t _{PHL}			23	34		
t _{PLH}	POL to Y _i		18	27	ns	
t _{PHL}			21	31		
t _{ZH}	\overline{OE} Control to Y _i		22	33	ns	
t _{ZL}			14	21		
t _{HZ}	\overline{OE} Control to Y _i		19	28	ns	C _L = 5.0pF R _L = 2.0kΩ
t _{LZ}			23	34		

SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t _{PLH}	A, B, C, D to Y _i		41		48	ns	C _L = 50pF R _L = 2.0kΩ
t _{PHL}			32		39		
t _{PLH}	E ₁ to Y _i		34		40	ns	
t _{PHL}			38		45		
t _{PLH}	\overline{E}_2 to Y _i		38		45	ns	
t _{PHL}			42		49		
t _{PLH}	POL to Y _i		32		37	ns	
t _{PHL}			42		52		
t _{ZH}	\overline{OE} Control to Y _i		44		55	ns	
t _{ZL}			23		25		
t _{HZ}	\overline{OE} Control to Y _i		33		37	ns	C _L = 5.0pF R _L = 2.0kΩ
t _{LZ}			38		42		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

FUNCTION TABLE

FUNCTION	INPUTS								OUTPUTS									
	\overline{OE}	$\overline{E_1}$	E_2	POL	D	C	B	A	Y_0	Y_1	Y_2	Y_3	Y_4	Y_5	Y_6	Y_7	Y_8	Y_9
3-State	H	X	X	X	X	X	X	X	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z
Disable	L	H	X	L	X	X	X	X	L	L	L	L	L	L	L	L	L	L
	L	H	X	H	X	X	X	X	H	H	H	H	H	H	H	H	H	H
	L	X	L	L	X	X	X	X	L	L	L	L	L	L	L	L	L	L
	L	X	L	H	X	X	X	X	H	H	H	H	H	H	H	H	H	H
Active-HIGH Output	L	L	H	L	L	L	L	L	H	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	H	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	H	L	L	L	L	H	L	L	L	L	L	L	L	L	L	L
	Active-LOW Output	L	L	H	H	L	L	L	L	L	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H
L		L	H	H	L	L	L	H	L	H	H	H	H	H	H	H	H	H

H = HIGH
L = LOWX = Don't Care
Z = High Impedance

DEFINITION OF FUNCTIONAL TERMS

A, B, C, D To select inputs to the decoder.**E1** The active-LOW enable input. A HIGH on the E1 input inhibits the decoder function regardless of any other inputs. **$\overline{E2}$** The active-HIGH enable input. A LOW on the $\overline{E2}$ input forces all the decoder functions to the inactive state regardless of any other inputs.**POL**

The polarity control for the output function. When the polarity control is HIGH, the outputs are active-LOW. When the POL input is LOW, the outputs are active-HIGH.

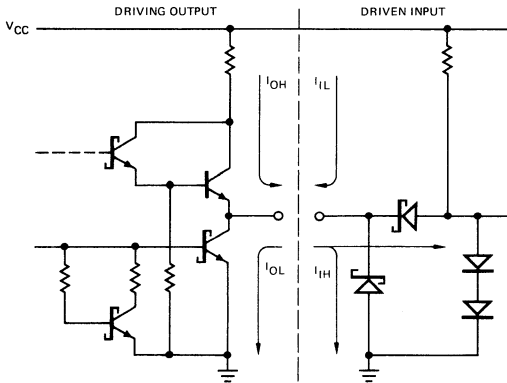
 \overline{OE}

Output Enable. An active-LOW three-state control used to enable the outputs. A HIGH level input forces the output to the high impedance (off) state.

 Y_i

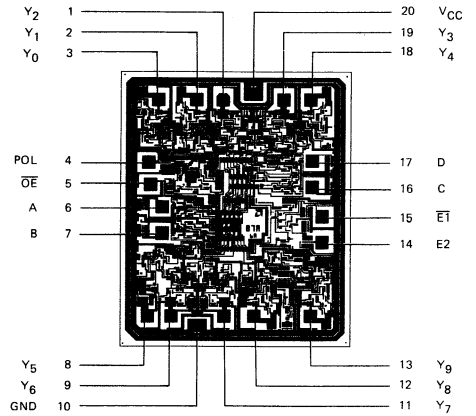
Decoder outputs. The ten outputs of the decoder.

Am25LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS



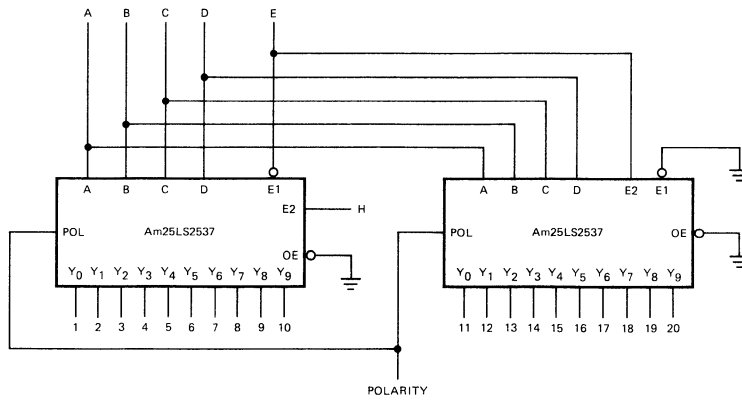
Note: Actual current flow direction shown.

Metallization and Pad Layout

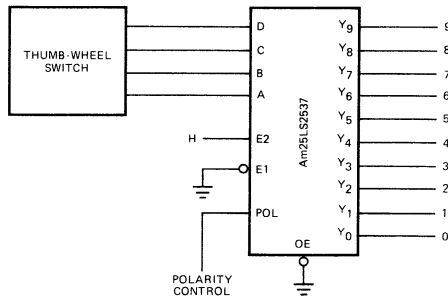


DIE SIZE 0.081" X 0.096"

APPLICATIONS



One-of-Twenty Decoder with Active-High or Active-Low Output Polarity.
 Could be used for I/O Decoding in an Am9080A system.



BCD to Decimal (One-of-Ten) Decoder.

Am25LS2538

74ALS538

One-of-Eight Decoder With Three-State Outputs And Polarity Control

DISTINCTIVE CHARACTERISTICS

- Three-state decoder outputs
- Buffered common output polarity control
- Inverting and non-inverting enable inputs
- A. C. parameters specified over operating temperature and power supply ranges
- 100% product assurance screening to MIL-STD-883 requirements

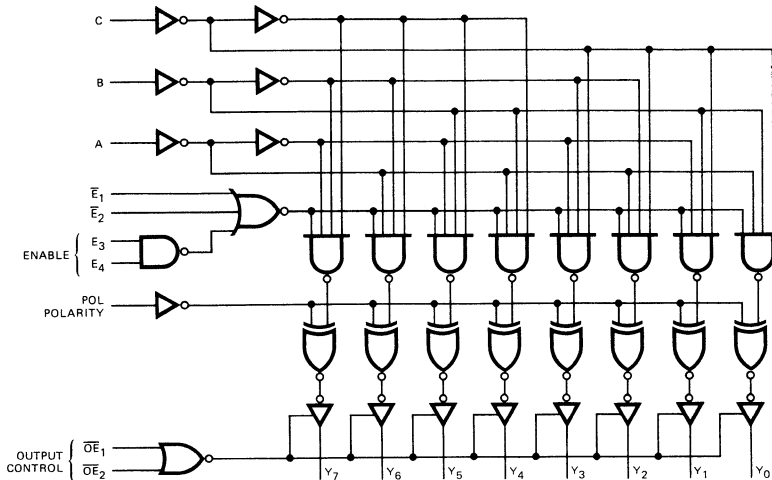
FUNCTIONAL DESCRIPTION

The Am25LS2538 is a three-line to eight-line decoder/demultiplexer fabricated using advanced Low-Power Schottky technology. The decoder has three buffered select inputs—A, B, and C—that are decoded to one-of-eight Y outputs. Two active-HIGH and two active-LOW enables can be used for gating the decoder or can be used with incoming data for demultiplexing applications.

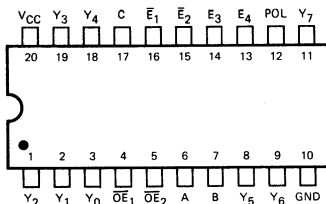
A separate polarity (POL) input can be used to force the function active-HIGH or active-LOW at the output. Two separate active-LOW output enables (\overline{OE}) inputs are provided. If either \overline{OE} input is HIGH, the output is in the high impedance (off) state. When the POL input is LOW, the Y outputs are active-HIGH and when the POL input is HIGH, the Y outputs are active-LOW.

The device is packaged in a space saving (0.3-inch row spacing) 20-pin package. It also features Am25LS family improved switching specifications, higher noise margin, and twice the fan-out over the military temperature range when compared with Am54LS/74LS devices.

LOGIC DIAGRAM One-of-Eight Decoder

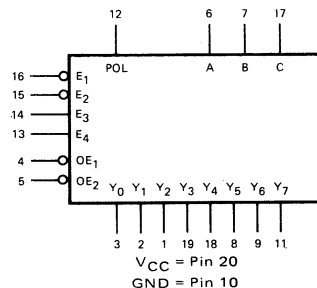


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



3

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\%$	MIN. = 4.75 V	MAX. = 5.25 V
MIL	$T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\%$	MIN. = 4.50 V	MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -1.0\text{mA}$ (MIL)	2.4	3.4		Volts
			$I_{OH} = -2.6\text{mA}$ (COM'L)	2.4	3.4		
V_{OL}	Output LOW Voltage (Note 5)	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4.0\text{mA}$			0.4	Volts
			$I_{OL} = 8.0\text{mA}$			0.45	
			$I_{OL} = 12\text{mA}$			0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$				-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$				-0.36	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$				20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 7.0\text{V}$				0.1	mA
I_{OZ}	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$			-20	μA
			$V_O = 2.4\text{V}$			20	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$		-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$			21	34	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Test conditions: A = B = C = $\bar{E}_1 = \bar{E}_2 = \text{GND}$; $E_3 = E_4 = \text{POL} = \bar{O}\bar{E}_1 = \bar{O}\bar{E}_2 = 4.5\text{V}$.
 5. V_{OL} is specified with total device $I_{OL} = 60\text{mA}$ (max.).

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to $+V_{CC}$ max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	A, B, C to Y_i		20	30	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			15	22		
t_{PLH}	$\overline{E}_1, \overline{E}_2$ to Y_i		19	28	ns	
t_{PHL}			20	30		
t_{PLH}	E_3, E_4 to Y_i		21	31	ns	
t_{PHL}			23	34		
t_{PLH}	POL to Y_i		16	24	ns	
t_{PHL}			20	30		
t_{ZH}	$\overline{OE}_1, \overline{OE}_2$ to Y_i		17	25	ns	
t_{ZL}			14	21		
t_{HZ}	$\overline{OE}_1, \overline{OE}_2$ to Y_i		17	25	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{LZ}			20	30		

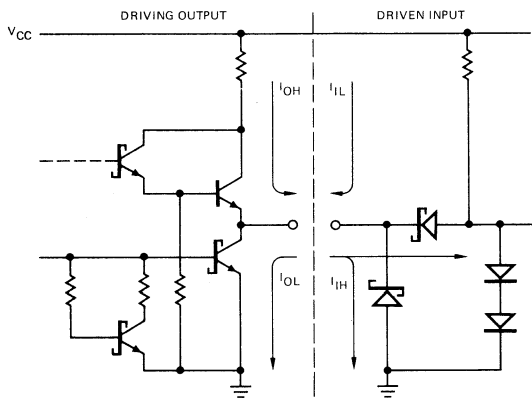
SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$			
t_{PLH}	A, B, C to Y_i		36		42	ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			29		37		
t_{PLH}	$\overline{E}_1, \overline{E}_2$ to Y_i		34		39	ns	
t_{PHL}			38		45		
t_{PLH}	E_3, E_4 to Y_i		38		45	ns	
t_{PHL}			43		52		
t_{PLH}	POL to Y_i		29		34	ns	
t_{PHL}			39		49		
t_{ZH}	$\overline{OE}_1, \overline{OE}_2$ to Y_i		38		45	ns	
t_{ZL}			23		25		
t_{HZ}	$\overline{OE}_1, \overline{OE}_2$ to Y_i		29		33	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{LZ}			33		36		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

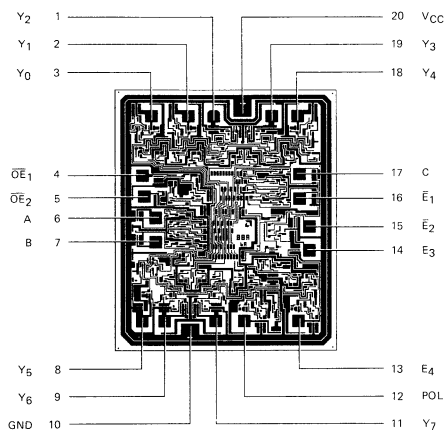
3

Am25LS LOW-POWER SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

Metallization and Pad Layout



DIE SIZE 0.081" X 0.096"

DEFINITION OF FUNCTIONAL TERMS

A, B, C, D The three select inputs to the decoder/demultiplexer.

\bar{E}_1, \bar{E}_2 The active LOW enable inputs. A HIGH on either the \bar{E}_1 or \bar{E}_2 input forces all decoded functions to be disabled.

E_3, E_4 The active LOW enable inputs. A LOW on either E_3 or E_4 inputs forces all the decoded functions to be inhibited.

POL Polarity Control. A LOW on the polarity con-

trol input forces the output to the active-HIGH state while a HIGH on the polarity control input forces the Y outputs to the active-LOW state.

\bar{OE}_1, \bar{OE}_2 Output Enable. When both the \bar{OE}_1 and \bar{OE}_2 inputs are LOW, the Y outputs are enabled. If either \bar{OE}_1 or \bar{OE}_2 input is HIGH, the Y outputs are in the high impedance state.

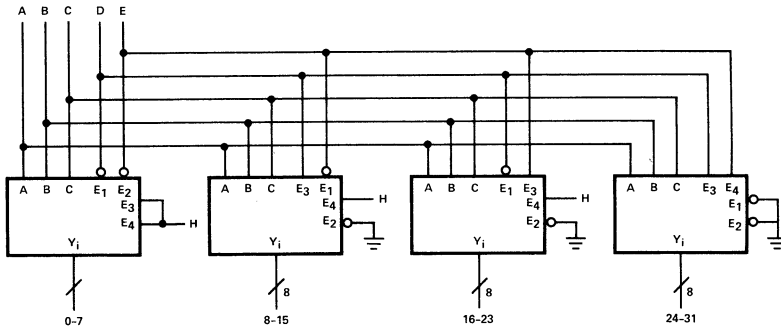
Y_i The eight outputs for the decoder/demultiplexer.

FUNCTION TABLE

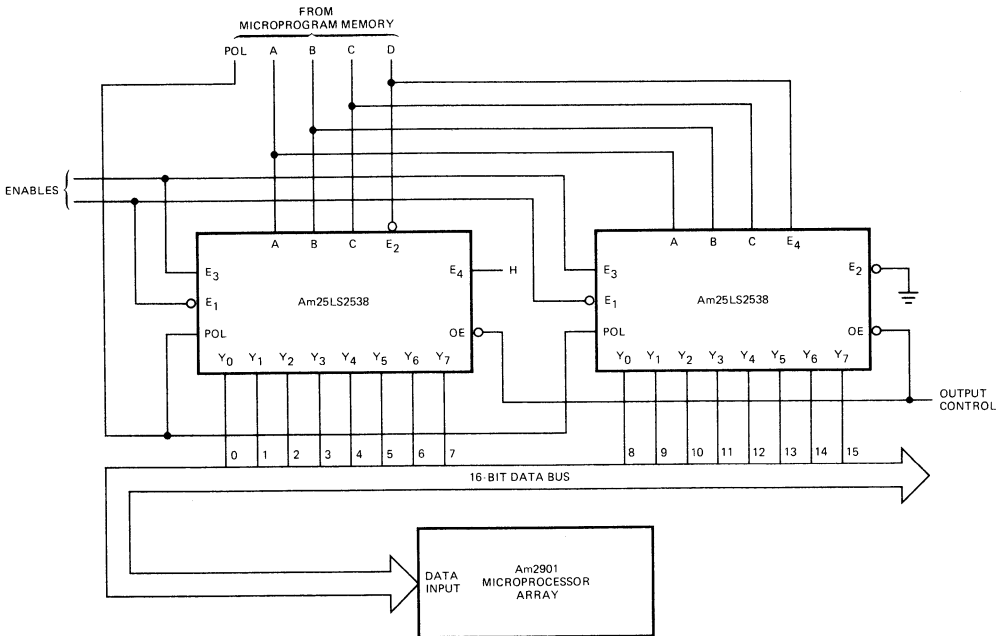
FUNCTION	INPUTS										OUTPUTS							
	\bar{OE}_1	\bar{OE}_2	\bar{E}_1	\bar{E}_2	E_3	E_4	POL	C	B	A	Y_0	Y_1	Y_2	Y_3	Y_4	Y_5	Y_6	Y_7
High Impedance	H X	X H	X X	X X	X X	X X	X X	X X	X X	X X	Z Z	Z Z	Z Z	Z Z	Z Z	Z Z	Z Z	Z Z
Disable	L	L	H	X	X	X	L	X	X	X	L	L	L	L	L	L	L	L
	L	L	H	X	X	X	H	X	X	X	H	H	H	H	H	H	H	H
	L	L	X	H	X	X	L	X	X	X	L	L	L	L	L	L	L	L
	L	L	X	H	X	X	H	X	X	X	H	H	H	H	H	H	H	H
	L	L	X	X	L	X	L	X	X	X	L	L	L	L	L	L	L	L
	L	L	X	X	L	X	H	X	X	X	H	H	H	H	H	H	H	H
	L	L	X	X	X	L	H	X	X	X	H	H	H	H	H	H	H	H
Active-HIGH Output	L	L	L	L	H	H	L	L	L	L	H	L	L	L	L	L	L	L
	L	L	L	L	H	H	L	L	L	H	L	L	L	L	L	L	L	L
	L	L	L	L	H	H	L	L	H	H	L	L	L	L	L	L	L	L
	L	L	L	L	H	H	L	H	L	L	L	L	L	L	L	L	L	L
	L	L	L	L	H	H	L	H	L	H	L	L	L	L	L	L	L	L
	L	L	L	L	H	H	L	H	H	L	L	L	L	L	L	L	L	L
	L	L	L	L	H	H	L	H	H	H	L	L	L	L	L	L	L	L
Active-LOW Output	L	L	L	L	H	H	H	L	L	L	L	H	H	H	H	H	H	H
	L	L	L	L	H	H	H	L	H	L	H	L	L	L	L	L	L	L
	L	L	L	L	H	H	H	L	H	L	H	H	H	H	H	H	H	H
	L	L	L	L	H	H	H	L	H	L	H	H	H	H	H	H	H	H
	L	L	L	L	H	H	H	L	H	L	H	H	H	H	H	H	H	H
	L	L	L	L	H	H	H	L	H	L	H	H	H	H	H	H	H	H
	L	L	L	L	H	H	H	L	H	L	H	H	H	H	H	H	H	H

H = HIGH L = LOW X = Don't Care Z = High Impedance

APPLICATIONS



One-of-thirty two decoder without additional decoding devices.
 Can be used for I/O decoding in an Am9080A system.



Two Am25LS2538s can be used to perform a one-of-sixteen-bit mask function or a one-of-sixteen-bit select function to perform bit manipulation in a microprocessor system.

Examples:

D	C	B	A	POL	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	Function	
0	0	1	1	0	0	0	0	1	0	0	0	0	0	0	0	0	0	0	0	0	0	Bit Select
1	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1	0	0	Bit Select
0	1	1	0	1	1	1	1	1	1	0	1	1	1	1	1	1	1	1	1	1	1	Bit Mask
1	0	1	0	1	1	1	1	1	1	1	1	1	1	1	0	1	1	1	1	1	1	Bit Mask

3

Am25LS2539

Dual One-Of-Four Decoder With Three-State Outputs And Polarity Control

DISTINCTIVE CHARACTERISTICS

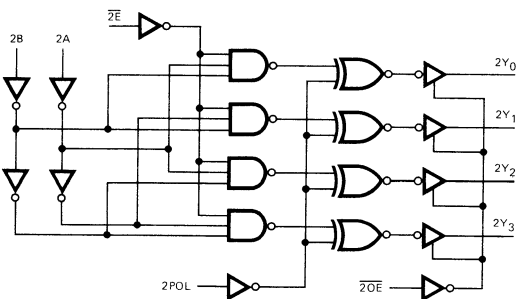
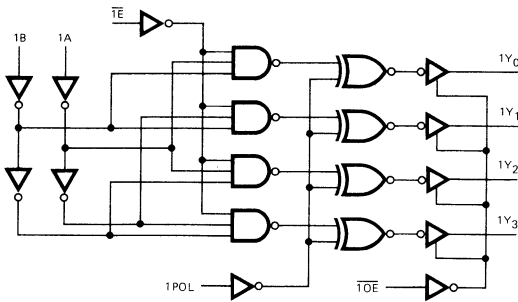
- Two independent decoders/demultiplexers
- Three-state outputs
- Buffered common polarity control
- A. C. parameters specified over operating temperature and power supply ranges
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

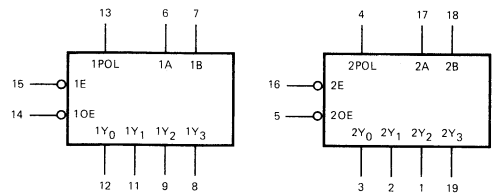
The Am25LS2539 is a dual two-line to four-line decoder/demultiplexer fabricated using advanced Low-Power Schottky technology. Each decoder has two buffered select inputs—A and B which are decoded to one-of-four Y outputs. An enable input (\overline{E}) is used for gating or can be used as a data input for demultiplexing applications. When the enable input goes HIGH, all four decoder functions are inhibited.

An output enable (\overline{OE}) input is used to control the three-state outputs of the device. When the \overline{OE} input is LOW, the outputs are enabled. When the \overline{OE} input is HIGH, the outputs are in the high impedance (off) state. The device also has separate buffered polarity (POL) inputs to force the outputs to either an active-HIGH state or an active-LOW state. When the POL input is LOW, the outputs are active-HIGH and when the POL input is HIGH, the outputs are active-LOW. The device is packaged in a space saving (0.3 inch row spacing) 20-pin package. The device features Am25LS family improved switching specification, higher noise margin, and twice the fan-out over the military temperature range when compared with Am54LS/74LS devices.

LOGIC DIAGRAM

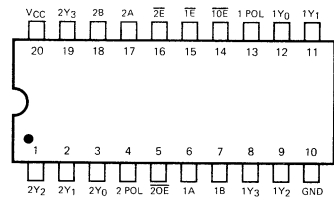


LOGIC SYMBOLS



V_{CC} = Pin 20
GND = Pin 10

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{ V} \pm 5\%$	MIN. = 4.75 V	MAX. = 5.25 V
MIL	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{ V} \pm 10\%$	MIN. = 4.50 V	MAX. = 5.50 V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL, $I_{OH} = -1.0\text{mA}$	2.4	3.4	Volts
			COM'L, $I_{OH} = -2.6\text{mA}$	2.4	3.4	
V_{OL}	Output LOW Voltage (Note 5)	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4.0\text{mA}$		0.4	Volts
			$I_{OL} = 8.0\text{mA}$		0.45	
			$I_{OL} = 12\text{mA}$		0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{ V}$			-0.36	mA
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{ V}$			20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{ V}$			0.1	mA
I_{OZ}	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{ V}$		-20	μA
			$V_O = 2.4\text{ V}$		20	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$	-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$		22	37	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{ V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Test conditions: $A = B = \bar{E} = \text{GND}$; $POL = \bar{OE} = 4.5\text{V}$.
 5. V_{OL} is specified with total device $I_{OL} = 60\text{mA}$ (max.).

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	$-65^\circ\text{C to } +150^\circ\text{C}$
Temperature (Ambient) Under Bias	$-55^\circ\text{C to } +125^\circ\text{C}$
Supply Voltage to Ground Potential Continuous	$-0.5\text{ V to } +7.0\text{ V}$
DC Voltage Applied to Outputs for High Output State	$-0.5\text{ V to } +V_{CC} \text{ max.}$
DC Input Voltage	$-0.5\text{ V to } +7.0\text{ V}$
DC Output Current, Into Outputs	30mA
DC Input Current	$-30\text{mA to } +5.0\text{mA}$

SWITCHING CHARACTERISTICS

($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

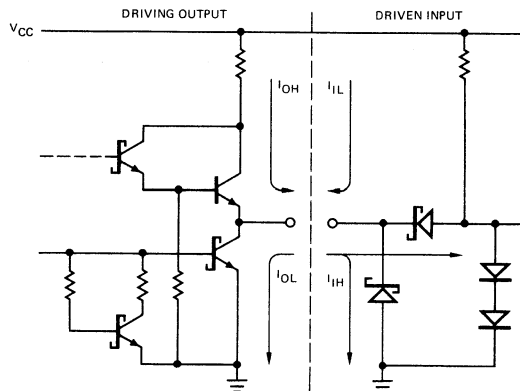
Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t_{PLH}	A, B to Y_i		22	33	ns	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			17	25		
t_{PLH}	\bar{E} to Y_i		19	28	ns	
t_{PHL}			21	31		
t_{PLH}	POL to Y_i		16	24	ns	
t_{PHL}			19	28		
t_{ZH}	\overline{OE} to Y_i		15	23	ns	
t_{ZL}			15	22		
t_{HZ}	\overline{OE} to Y_i		19	28	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{LZ}			23	34		

SWITCHING CHARACTERISTICS OVER OPERATING RANGE*

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	A, B, to Y_i	$T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$		$T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$		ns	$C_L = 50\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{PHL}			41		48		
PLH	\bar{E} to Y_i		34		42	ns	
t_{PHL}			34		40		
t_{PLH}	POL to Y_i		38		45	ns	
t_{PHL}			29		34		
t_{ZH}	\overline{OE} to Y_i		39		49	ns	
t_{ZL}			38		45		
t_{HZ}	\overline{OE} to Y_i		24		25	ns	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$
t_{LZ}			33		37		
			36		37		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

**Am25LS • Am54LS/74LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS**



Note: Actual current flow direction shown.

DEFINITION OF FUNCTIONAL TERMS

A, B Select the two select inputs to the decoder/demultiplexer.

\bar{E} Enable The enable input to the decoder. A HIGH input forces the decoding functions to be inhibited regardless of the A and B inputs.

POL Polarity Input. The polarity input forces the outputs either an active-HIGH state or an active-LOW state. A LOW on the polarity input forces the output active-HIGH. A HIGH on the polarity input forces the outputs active-LOW.

\bar{OE} Output Enable. A LOW on the \bar{OE} input enables the outputs. A HIGH on the \bar{OE} inputs forces the outputs to the high impedance (off) state.

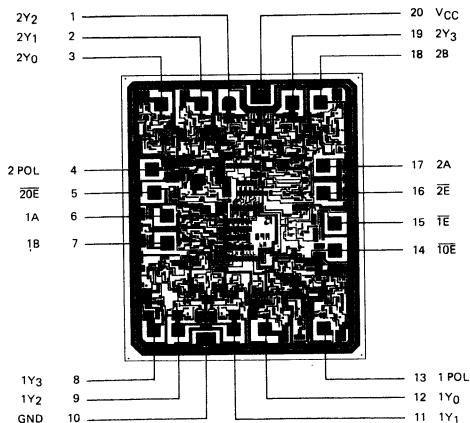
Y_0, Y_1, Y_2, Y_3 The four decoder/demultiplexer outputs.

FUNCTION TABLE

Function	Inputs					Outputs			
	\bar{OE}	\bar{E}	POL	B	A	Y_0	Y_1	Y_2	Y_3
High Impedance	H	X	X	X	X	Z	Z	Z	Z
Disable	L	H	L	X	X	L	L	L	L
	L	H	H	X	X	H	H	H	H
Active-High Output	L	L	L	L	L	H	L	L	L
	L	L	L	L	H	L	H	L	L
	L	L	L	H	L	L	L	H	L
	L	L	L	H	H	L	L	L	H
Active-Low Output	L	L	H	L	L	L	H	H	H
	L	L	H	L	H	H	L	H	H
	L	L	H	H	L	H	H	L	H
	L	L	H	H	H	H	H	H	L

H = HIGH X = Don't Care
L = LOW Z = High Impedance

Metallization and Pad Layout

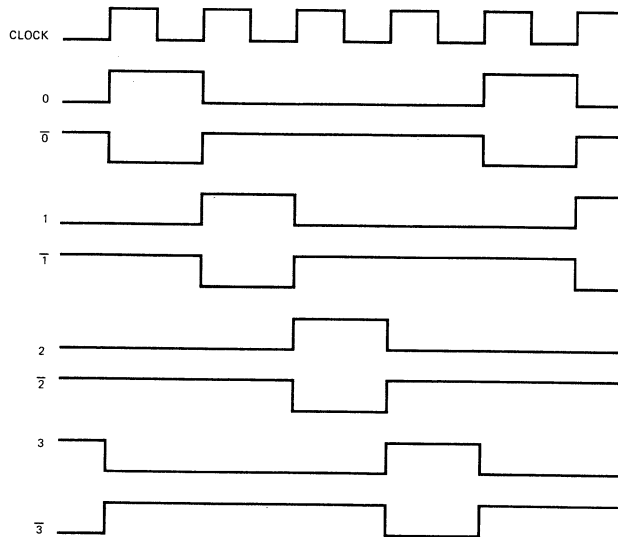
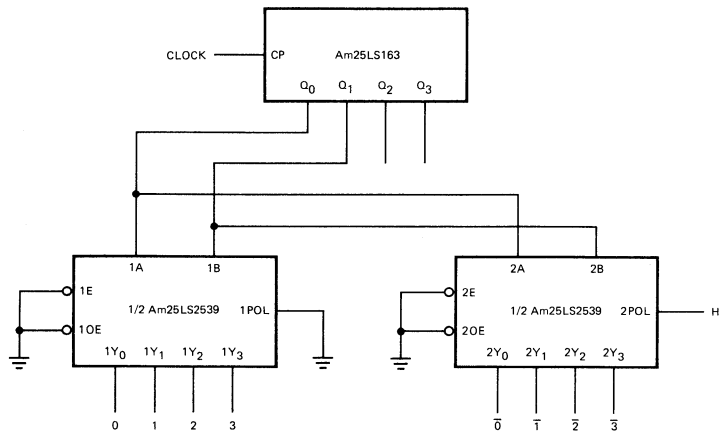


DIE SIZE 0.081" X 0.096"

ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM25LS2539PC
Hermetic DIP	0°C to +70°C	AM25LS2539DC
Dice	0°C to +70°C	AM25LS2539XC
Hermetic DIP	-55°C to +125°C	AM25LS2539DM
Hermetic Flat Pak	-55°C to +125°C	AM25LS2539FM
Dice	-55°C to +125°C	AM25LS2539XM

APPLICATIONS



FOUR PHASE CLOCK GENERATOR

Am25LS2568 • Am25LS2569

Four-Bit Up/Down Counters With Three-State Outputs

DISTINCTIVE CHARACTERISTICS

- 4-bit synchronous counter, synchronously programmable
- Both synchronous and asynchronous clear inputs
- Three-state counter outputs interface directly with bus organized systems
- Internal look-ahead carry logic and two count enable lines for high speed cascaded operation
- Ripple carry output for cascading
- Clock carry output for convenient modulo configuration
- Fully buffered outputs
- Second sourced as the 54LS/74LS568 and LS569
- Advanced low-power Schottky technology
- 100% product assurance screening to MIL-STD-883 requirements

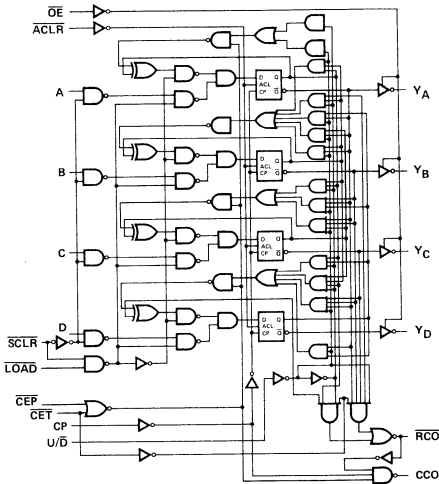
FUNCTIONAL DESCRIPTION

The Am25LS2568 and Am25LS2569 are programmable up/down BCD and Binary counters respectively with three-state outputs for bus organized systems. All functions except output enable (\overline{OE}) and asynchronous clear (\overline{ACLR}) occur on the positive edge of the clock input (CP).

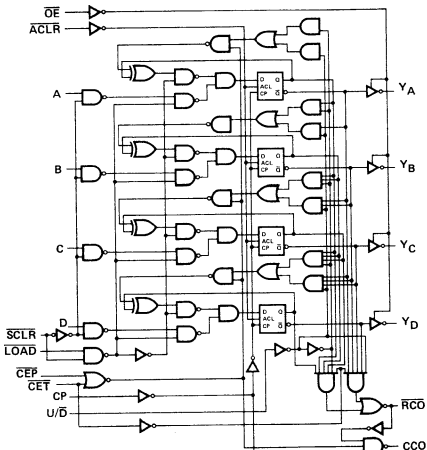
With the \overline{LOAD} input LOW, the outputs will be programmed by the parallel data inputs (A, B, C, D) on the next clock edge. Counting is enabled only when \overline{CEP} and \overline{CET} are LOW and \overline{LOAD} is HIGH. The up-down input (U/\overline{D}) controls the direction of count, HIGH counts up and LOW counts down. Internal look-ahead carry logic and an active LOW ripple carry output (\overline{RCO}) allows for high-speed counting and cascading. During up-count, the \overline{RCO} is LOW at binary 9 for the LS2568 (binary 15 for the LS2569) and upon down-count, it is LOW at binary 0. Normal cascaded operations requires only the \overline{RCO} to be connected to the succeeding block at \overline{CET} . When counting, the clocked carry output (CCO) provides a HIGH-LOW-HIGH pulse for a duration equal to the LOW time of the clock pulse and only when \overline{RCO} is LOW. Two active LOW reset lines are available, synchronous clear (\overline{SCLR}) and a master reset asynchronous clear (\overline{ACLR}). The output control (\overline{OE}) input forces the counter output into the high impedance state when HIGH and when LOW, the counter outputs are enabled.

LOGIC DIAGRAMS

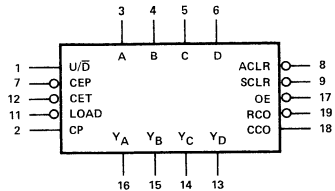
Am25LS2568



Am25LS2569



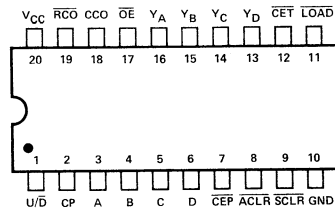
LOGIC SYMBOL



V_{CC} = Pin 20

GND = Pin 10

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Specified:

COM'L $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$ MIN. = 4.75V MAX. = 5.25VMIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$ MIN. = 4.50V MAX. = 5.50V

DC CHARACTERISTICS OVER OPERATING RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units	
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	Y_i	MIL, $I_{OH} = -1.0\text{mA}$	2.4	3.4		Volts
				COM'L, $I_{OH} = -2.6\text{mA}$	2.4	3.2		
		\overline{RCO} , CCO	$I_{OH} = -440\mu\text{A}$	MIL	2.5	3.4		
				COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 4.0\text{mA}$				0.4	Volts
			$I_{OL} = 8.0\text{mA}$				0.45	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs			2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs		MIL			0.7	Volts
				COM'L			0.8	
V_I	Input Clamp Voltage	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$					-1.5	Volts
I_{IL}	Input LOW Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$	\overline{ACLR} , \overline{OE} , $\overline{U/D}$, \overline{Load}				0.3	mA
			A, B, C, D, CP, \overline{CEP}				0.4	
			\overline{CET} , \overline{SCLR}				0.65	
I_{IH}	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$					20	μA
I_I	Input HIGH Current	$V_{CC} = \text{MAX.}$, $V_{IN} = 7.0\text{V}$					0.1	mA
I_{OZ}	Off-State (High-Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 0.4\text{V}$				-20	μA
			$V_O = 2.4\text{V}$				20	
I_{SC}	Output Short Circuit Current (Note 3)	$V_{CC} = \text{MAX.}$			-15		-85	mA
I_{CC}	Power Supply Current (Note 4)	$V_{CC} = \text{MAX.}$				28	43	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
4. $\overline{OE} = \text{HIGH}$, all other inputs = GND, all outputs open.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5V to +7.0V
DC Voltage Applied to Outputs for High Output State	-0.5V to V_{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

SWITCHING CHARACTERISTICS

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Min.	Typ.	Max.	Units	Test Conditions
t _{PLH}	Clock to Any Q; Load = LOW		12	18	ns	C _L = 15pF R _L = 2.0kΩ
t _{PHL}			18	27		
t _{PLH}	Clock to Any Q; Load = HIGH		12	18	ns	
t _{PHL}			18	27		
t _{PLH}	CET to RCO		11	16	ns	
t _{PHL}			6	10		
t _{PLH}	U/D to RCO		15	23	ns	
t _{PHL}			13	20		
t _{PLH}	Clock to RCO		24	35	ns	
t _{PHL}			16	24		
t _{PLH}	Clock to CCO		10	15	ns	
t _{PHL}			8	13		
t _{PLH}	CET or CEP to CCO		8	12	ns	
t _{PHL}			17	25		
t _{PLH}	ACLR to Any Q		N.A.	N.A.	ns	
t _{PHL}			17	26		
t _s	Set-up	A, B, C, D	20		ns	
		SCLR	20			
		Load	30			
		U/D	30			
		CET, CEP	25			
t _s	SCLR Recovery (inactive) to Clock	28			ns	
t _h	Data Hold	0			ns	
f _{max}	Maximum Clock Frequency (Note 1)	25	40		MHz	
t _{pw}	Clock Pulse Width	20			ns	
t _{PZH}	OE to Any Q; Enable			11	ns	
t _{PZL}				19		
t _{PHZ}	OE to Any Q; Disable			18	ns	
t _{PLZ}				24		

3

Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

FUNCTION TABLE

CP	INPUTS										OUTPUTS					FUNCTION		
	D	C	B	A	LOAD	CET	CEP	V/D	ACLR	SCLR	OE	RCO	CCO	Y _D	Y _C		Y _B	Y _A
↑	X	X	X	X	H	L	L	H	H	H	L	A/R	A/R	(Q _T - CP) + 1				Count up
↑	X	X	X	X	H	L	L	L	H	H	L	A/R	A/R	(Q _T - CP) - 1				Count Down
↑	X	X	X	X	H	H	X	X	H	H	L	H	H	NC	NC	NC	NC	Count Inhibit
↑	X	X	X	X	H	L	H	X	H	H	L	A/R	H	NC	NC	NC	NC	Count Inhibit
∏	X	X	X	X	X	L	L	H	H	H	L	L	∏	H	H	H	H	Overflow (LS2569)
↑	X	X	X	X	X	L	H	H	H	H	L	L	H	H	H	H	H	Overflow (LS2569)
∏	X	X	X	X	X	L	L	H	H	H	L	L	∏	H	L	L	H	Overflow (LS2568)
↑	X	X	X	X	X	L	H	H	H	H	L	L	H	H	L	L	H	Overflow (LS2568)
↑	X	X	X	X	X	H	X	H	H	H	L	H	H	H	H	H	H	Overflow Inhibit (LS2569)
∏	X	X	X	X	X	H	X	H	H	H	L	H	H	H	L	L	H	Overflow Inhibit (LS2568)
∏	X	X	X	X	X	L	L	L	H	H	L	L	∏	L	L	L	L	Underflow
↑	X	X	X	X	X	L	H	L	H	H	L	L	H	L	L	L	L	Underflow
↑	X	X	X	X	X	H	X	L	H	H	L	H	H	L	L	L	L	Underflow Inhibit
↑	L	H	L	H	L	X	X	X	H	H	L	H	H	L	H	L	H	Load Example
↑	X	X	X	X	X	X	X	X	H	H	L	H	H	L	L	L	L	Clear (Synchronous)
∏	X	X	X	X	X	L	L	L	H	L	L	L	∏	L	L	L	L	Clear (Synchronous)
↑	X	X	X	X	X	L	L	L	H	L	L	L	H	L	L	L	L	Clear (Synchronous)
↑	X	X	X	X	X	H	X	L	H	L	L	H	H	L	L	L	L	Clear (Synchronous)
X	X	X	X	X	X	X	X	X	H	L	X	L	H	L	L	L	L	Asynchronous Clear
∏	X	X	X	X	X	L	L	L	L	L	X	L	∏	L	L	L	L	Asynchronous Clear
X	X	X	X	X	X	L	H	L	L	L	X	L	H	L	L	L	L	Asynchronous Clear
X	X	X	X	X	X	H	X	L	L	L	X	L	H	L	L	L	L	Asynchronous Clear
X	X	X	X	X	X	X	X	X	X	X	H	X	X					Output Disabled

(Q_T - CP) = Output state prior to clock edge
NC = No change

A/R = Assumes required output state;
High except during Overflow and Underflow

X = Don't care

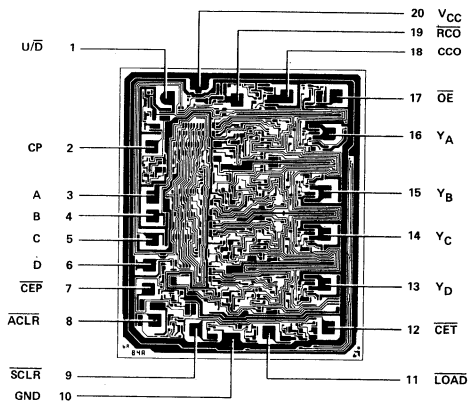
**SWITCHING CHARACTERISTICS
OVER OPERATING RANGE***

Parameters	Description	Am25LS COM'L		Am25LS MIL		Units	Test Conditions
		Min.	Max.	Min.	Max.		
t_{PLH}	Clock to Any Q; Load = LOW		22		24	ns	$C_L = 50pF$ $R_L = 2.0k\Omega$
t_{PHL}			35		40		
t_{PLH}	Clock to Any Q; Load = HIGH		22		24	ns	
t_{PHL}			35		40		
t_{PLH}	\overline{CET} to \overline{RCO}		18		19	ns	
t_{PHL}			17		21		
t_{PLH}	U/ \overline{D} to \overline{RCO}		26		28	ns	
t_{PHL}			26		30		
t_{PLH}	Clock to \overline{RCO}		39		40	ns	
t_{PHL}			33		39		
t_{PLH}	Clock to CCO		17		18	ns	
t_{PHL}			22		27		
t_{PLH}	\overline{CET} or \overline{CEP} to CCO		16		17	ns	
t_{PHL}			36		45		
t_{PLH}	\overline{ACLR} to Any Q		N.A.		N.A.	ns	
t_{PHL}			37		45		
t_s	Set-up	A, B, C, D	25		30	ns	
		\overline{SCLR}	25		30		
		Load	38		45		
		U/ \overline{D}	40		50		
		\overline{CET} , \overline{CEP}	33		40		
t_s	SCLR Recovery (inactive) to Clock	39		50	ns		
t_h	Data Hold	0		5	ns		
f_{max}	Maximum Clock Frequency (Note 1)	20		18	MHz		
t_{pw}	Clock Pulse Width	27		35	ns		
t_{ZH}	\overline{OE} to Any Q; Enable		15		17	ns	
t_{ZL}			26		19		
t_{HZ}	\overline{OE} to Any Q; Disable		23		27	ns	
t_{LZ}			30		36		

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.
N.A. not applicable.

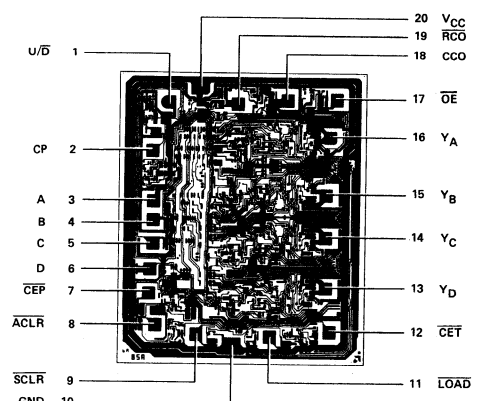
Metallization and Pad Layouts

Am25LS2568



DIE SIZE 0.087" X 0.103"

Am25LS2569

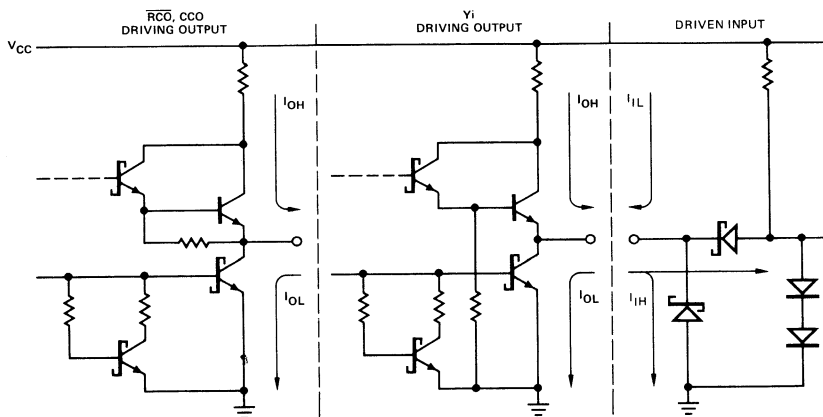


DIE SIZE 0.087" X 0.103"

DEFINITION OF FUNCTIONAL TERMS

A, B, C, D	The four programmable data inputs.	$\overline{\text{ACLR}}$	Asynchronous Clear. Master reset of counters to zero when $\overline{\text{ACLR}}$ is LOW, independent of the clock.
$\overline{\text{CEP}}$	Count Enable Parallel. Can be used to enable and inhibit counting in high speed cascaded operation. $\overline{\text{CEP}}$ must be LOW to count.	$\overline{\text{SCLR}}$	Synchronous clear of counters to zero on the next clock edge when $\overline{\text{SCLR}}$ is LOW.
$\overline{\text{CET}}$	Count Enable Trickle. Enables the ripple carry output for cascaded operation. Must be LOW to count.	$\overline{\text{OE}}$	A HIGH on the output control sets the four counter outputs in the high impedance, and a LOW, enables the output.
CP	Clock Pulse. All synchronous functions occur on the LOW-to-HIGH transition of the clock.	Y_A, Y_B, Y_C, Y_D	The four counter outputs.
$\overline{\text{LOAD}}$	Enables parallel load of counter outputs from data inputs on the next clock edge. Must be HIGH to count.	$\overline{\text{RCO}}$	Ripple Carry Output. Output will be LOW on the maximum count on up-count. Upon down-count, $\overline{\text{RCO}}$ is LOW at 0000.
$\text{U}/\overline{\text{D}}$	Up/Down Count Control. HIGH counts up and LOW counts down.	CCO	Clock Carry Output. While counting and $\overline{\text{RCO}}$ is LOW, CCO will follow the clock HIGH-LOW-HIGH transition.

Am25LS
LOW-POWER SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS

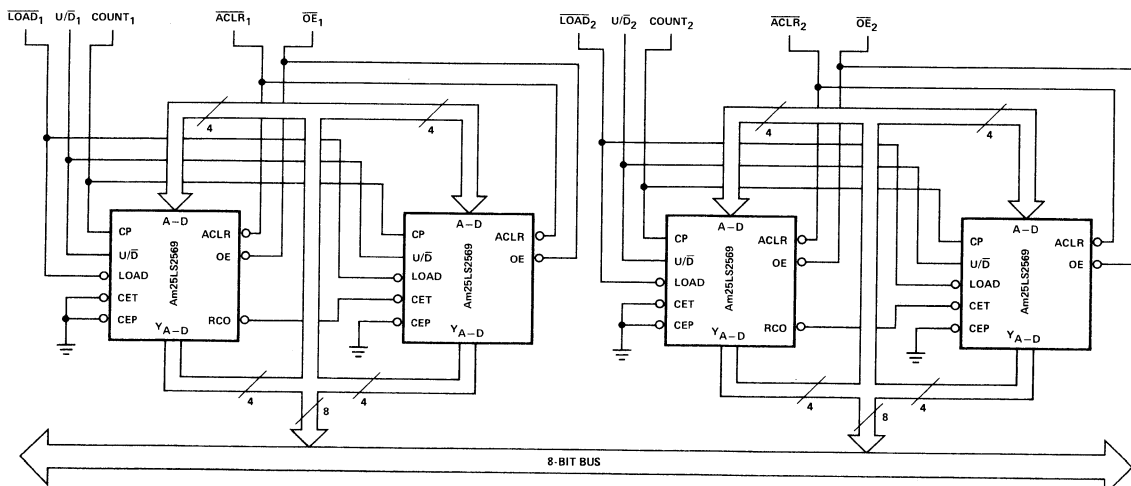


Note: Actual current flow direction shown.

ORDERING INFORMATION

Package Type	Temperature Range	Am25LS2568 Order Number	Am25LS2569 Order Number
Molded DIP	0°C to +70°C	AM25LS2568PC	AM25LS2569PC
Hermetic DIP	0°C to +70°C	AM25LS2568DC	AM25LS2569DC
Dice	0°C to +70°C	AM25LS2568XC	AM25LS2569XC
Hermetic DIP	-55°C to +125°C	AM25LS2568DM	AM25LS2569DM
Hermetic Flat Pak	-55°C to +125°C	AM25LS2568FM	AM25LS2569FM
Dice	-55°C to +125°C	AM25LS2568XM	AM25LS2569XM

APPLICATION



MICROPROGRAMMABLE DUAL-EVENT 8-BIT COUNTERS

Am26LS29

Quad Three-State Single Ended RS-423 Line Driver

DISTINCTIVE CHARACTERISTICS

- Four single ended line drivers in one package for maximum package density
- Output short-circuit protection
- Individual rise time control for each output
- 50Ω transmission line drive capability
- High capacitive load drive capability
- Low I_{CC} and I_{EE} power consumption (26mW/driver typ.)
- Meets all requirements of RS-423
- Three-state outputs for bus oriented systems
- Outputs do not clamp line with power off or in hi-impedance state over entire transmission line voltage range of RS-423
- Low current PNP inputs compatible with TTL, MOS and CMOS
- Available in military and commercial temperature range
- Advanced low power Schottky processing
- 100% reliability assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

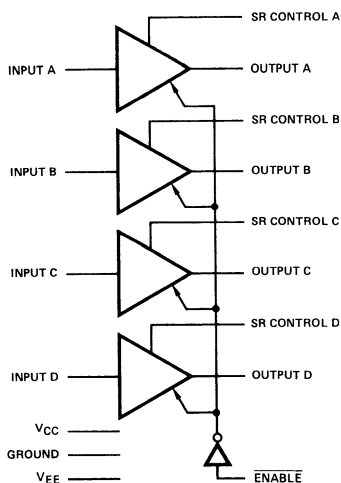
The Am26LS29 is a quad single ended line driver, designed for digital data transmission. The Am26LS29 meets all the requirements of EIA Standard RS-423 and Federal STD 1030. It features four buffered outputs with high source and sink current, and output short circuit protection.

A slew rate control pin allows the use of an external capacitor to control slew rate for suppression of near end cross talk to receivers in the cable.

The Am26LS29 has three-state outputs for bus oriented systems. The outputs in the hi-impedance state will not clamp the line over the transmission line voltage of RS-423. A typical full duplex system would use the Am26LS29 line driver and up to twelve Am26LS32 line receivers or an Am26LS32 line receiver and up to thirty-two Am26LS29 line drivers with only one enabled at a time and all others in the three-state mode.

The Am26LS29 is constructed using advanced low-power Schottky processing.

LOGIC DIAGRAM



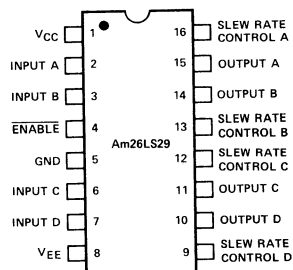
BLI-001

ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Hermetic DIP	-55°C to +125°C	AM26LS29DM
Hermetic Flat Pak	-55°C to +125°C	AM26LS29FM
Dice	-55°C to +125°C	AM26LS29XM
Hermetic DIP	0°C to +70°C	AM26LS29DC
Molded DIP	0°C to +70°C	AM26LS29PC
Dice	0°C to +70°C	AM26LS29XC

CONNECTION DIAGRAM

Top View



Note: Pin 1 is marked for orientation.

BLI-004

3

Am26LS29

ABSOLUTE MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Supply Voltage	
V+	7.0V
V-	-7.0V
Power Dissipation	600mW
Input Voltage	-0.5 to +15.0V
Output Voltage (Power Off)	±15V
Lead Soldering Temperature (10 seconds)	300°C

ELECTRICAL CHARACTERISTICS over the operating temperature range

The following conditions apply unless otherwise specified:

Am26LS29XM (MIL) $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$, $V_{EE} = -5.0\text{V} \pm 5\%$

Am26LS29XC (COM'L) $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$, $V_{EE} = -5.0\text{V} \pm 5\%$

DC CHARACTERISTICS over the operating temperature range (Notes 1 and 2)

Parameters	Description	Test Conditions	Min.	Typ. (Note 1)	Max.	Units	
$\frac{V_O}{V_O}$	Output Voltage	$R_L = \infty$	$V_{IN} = 2.4\text{V}$	4.0	4.4	6.0	Volts
			$V_{IN} = 0.4\text{V}$	-4.0	-4.4	-6.0	Volts
$\frac{V_T}{V_T}$	Output Voltage	$R_L = 450\Omega$	$V_{IN} = 2.4\text{V}$	3.6	4.1		Volts
			$V_{IN} = 0.4\text{V}$	-3.6	-4.1		Volts
$ V_T - V_T $	Output Unbalance	$ V_{CC} = V_{EE} $, $R_L = 450\Omega$		0.02	0.4	Volts	
I_{X+}	Output Leakage Power Off	$V_{CC} = V_{EE} = 0\text{V}$	$V_O = 10\text{V}$		2.0	100	μA
I_{X-}			$V_O = -10\text{V}$		-2.0	-100	μA
I_{S+}	Output Short Circuit Current	$V_O = 0\text{V}$	$V_{IN} = 2.4\text{V}$		-70	-150	mA
I_{S-}			$V_{IN} = 0.4\text{V}$		60	150	mA
I_{Slew}	Slew Control Current	$V_{SLEW} = V_{EE} + 0.9\text{V}$		±110		μA	
I_{CC}	Positive Supply Current	$V_{IN} = 2.4\text{V}$, $R_L = \infty$		15	25	mA	
I_{EE}	Negative Supply Current	$V_{IN} = 0.4\text{V}$, $R_L = \infty$		-9	-10	mA	
I_O	Off State (High Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_O = 10\text{V}$		2.0	100	μA
			$V_O = -10\text{V}$		-2.0	-100	μA
V_{IH}	High Level Input Voltage		2.0			Volts	
V_{IL}	Low Level Input Voltage				0.8	Volts	
I_{IH}	High Level Input Current	$V_{IN} = 2.4\text{V}$		1.0	40	μA	
		$V_{IN} \leq 15\text{V}$		10	100	μA	
I_{IL}	Low Level Input Current	$V_{IN} = 0.4\text{V}$		-30	-200	μA	
V_I	Input Clamp Voltage	$I_{IN} = -12\text{mA}$			-1.5	Volts	

AC CHARACTERISTICS

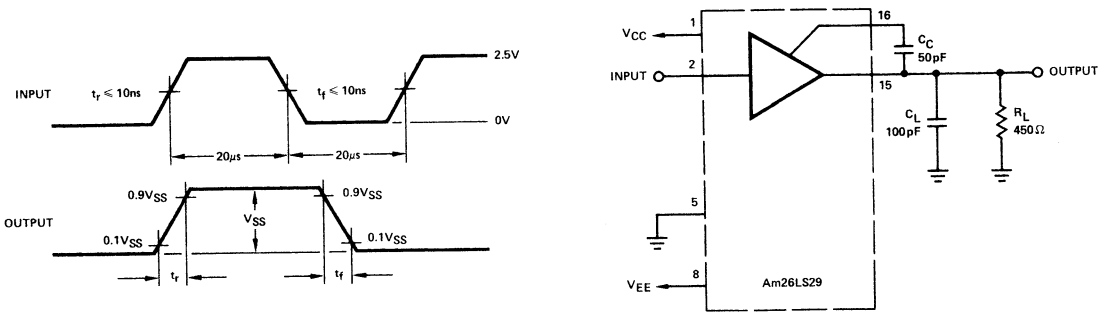
$V_{CC} = 5.0\text{V}$, $V_{EE} = -5.0\text{V}$, $T_A = 25^\circ\text{C}$

Parameters	Description	Test Conditions	Min.	Typ. (Note 1)	Max.	Units	
Sr+	Positive Slew Rate	$R_L = 450\Omega$, $C_L = 500\text{pF}$, Fig. 1	$C_C = 50\text{pF}$		3.0		μs
			$C_C = 0\text{pF}$		120	300	ns
Sr-	Negative Slew Rate	$R_L = 450\Omega$, $C_L = 500\text{pF}$, Fig. 1	$C_C = 50\text{pF}$		3.0		μs
			$C_C = 0\text{pF}$		120	300	ns
Src	Slew Rate Coefficient	$R_L = 450\Omega$, $C_L = 500\text{pF}$, Fig. 1		.06		$\mu\text{s/pF}$	
t_{LZ}	Output Enable to Output	$R_L = 450\Omega$, $C_L = 5.0\text{pF}$, $C_C = 0\text{pF}$		180	300	ns	
t_{HZ}				250	350		
t_{ZL}		$R_L = 450\Omega$, $C_L = 500\text{pF}$, $C_C = 0\text{pF}$		250	350		
t_{ZH}				180	300		

Notes: 1. Typical limits are at $V_{CC} = 5.0\text{V}$, $V_{EE} = -5.0\text{V}$, 25°C ambient and maximum loading.

2. Symbols and definitions correspond to EIA RS-423 where applicable.

SWITCHING TIME WAVEFORMS AND AC TEST CIRCUITS

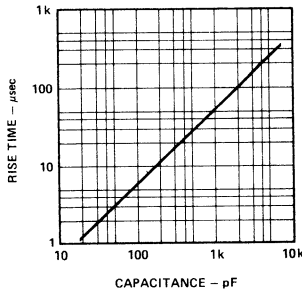


BLI-006

BLI-007

Figure 1. Rise Time Control.

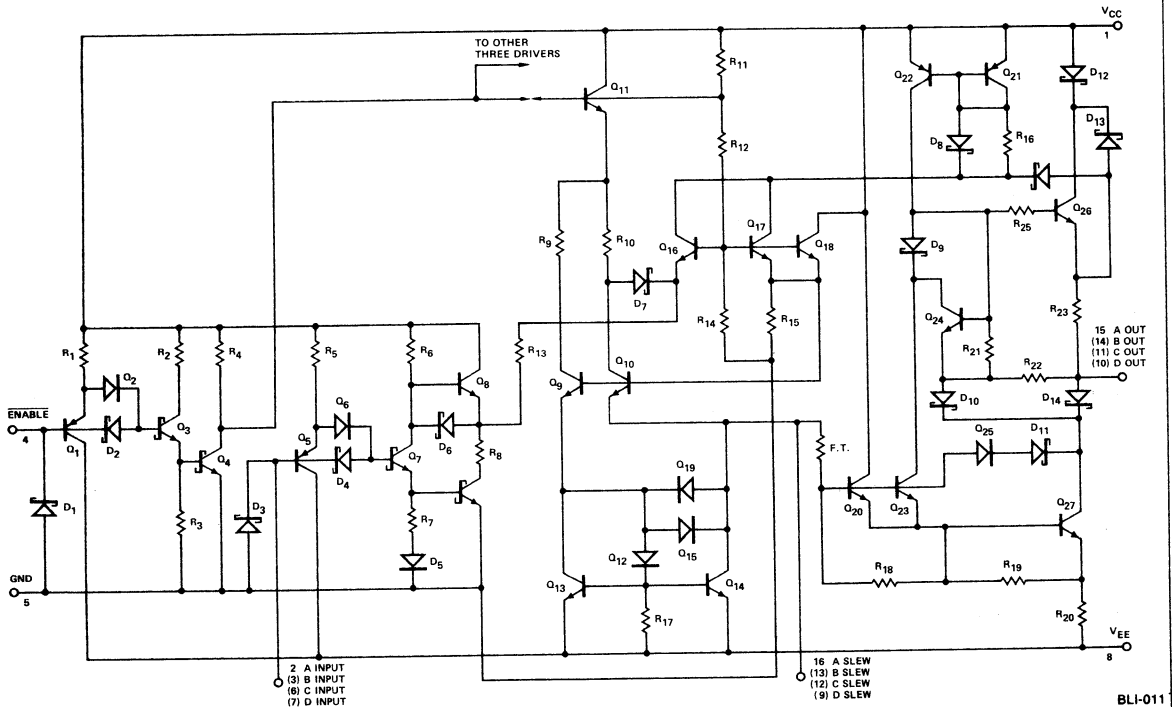
Slew Rate (Rise or Fall Time) Versus External Capacitor



CAPACITANCE - pF

BLI-010

Am26LS29 EQUIVALENT CIRCUIT



BLI-011

Am26LS30

Dual Differential RS-422 Party Line/Quad Single Ended RS-423 Line Driver

DISTINCTIVE CHARACTERISTICS

- Dual RS-422 line driver or quad RS-423 line driver
- Driver outputs do not clamp line with power off or in hi-impedance state
- Individually three-state drivers when used in differential mode
- Low I_{CC} and I_{EE} power consumption
 - RS-422 differential mode 35mW/driver typ.
 - RS-423 single-ended mode 26mW/driver typ.
- Individual slew rate control for each output
- 50Ω transmission line drive capability (RS-422 into virtual ground)
- Low current PNP inputs compatible with TTL, MOS and CMOS
- High capacitive load drive capability
- Exact replacement for DS16/3691
- Advanced low power Schottky processing
- 100% reliability assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am26LS30 is a line driver designed for digital data transmission. A mode control input provides a choice of operation either as two differential line drivers which meet all of the requirements of EIA Standard RS-422 or four independent single-ended RS-423 line drivers.

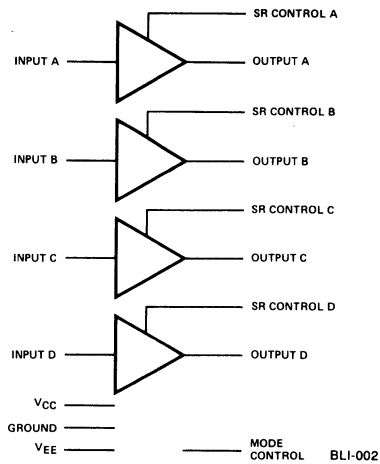
In the differential mode the outputs have individual three-state controls. In the hi-impedance state these outputs will not clamp the line over a common mode transmission line voltage of $\pm 10V$. A typical full duplex system would be the Am26LS30 differential line driver and up to twelve Am26LS32 line receivers or an Am26LS32 line receiver and up to thirty-two Am26LS30 differential drivers.

A slew rate control pin allows the use of an external capacitor to control slew rate for suppression of near end cross talk to receivers in the cable.

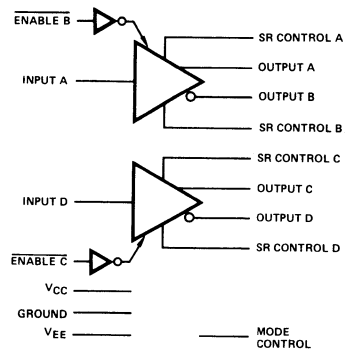
The Am26LS30 is constructed using Advanced Low Power Schottky processing.

LOGIC DIAGRAMS

Logic for Am26LS30 with Mode Control HIGH (RS-423)



Logic for Am26LS30 with Mode Control LOW (RS-422)

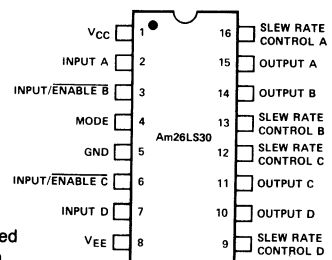


BLI-003

ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Hermetic DIP	-55°C to +125°C	AM26LS30DM
Hermetic Flat Pak	-55°C to +125°C	AM26LS30FM
Dice	-55°C to +125°C	AM26LS30XM
Hermetic DIP	0°C to +70°C	AM26LS30DC
Molded DIP	0°C to +70°C	AM26LS30PC
Dice	0°C to +70°C	AM26LS30XC

CONNECTION DIAGRAM – Top View



Note:
Pin 1 is marked for orientation.

BLI-005

ABSOLUTE MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Supply Voltage	
V+	7.0V
V-	-7.0V
Power Dissipation	600mW
Input Voltage	-0.5 to +15.0V
Output Voltage (Power Off)	±15V
Lead Soldering Temperature (10 seconds)	300°C

ELECTRICAL CHARACTERISTICS over the operating temperature range

The Following Conditions Apply Unless Otherwise Specified:

Am26LS30XM (MIL) $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$, $V_{EE} = \text{GND}$ Am26LS30XC (COM'L) $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$, $V_{EE} = \text{GND}$

EIA RS-422 Connection, Mode Voltage = 0.8V

DC CHARACTERISTICS over the operating temperature range

Parameters	Description	Test Conditions (Note 3)	Min.	Typ. (Note 1)	Max.	Units	
$\frac{V_O}{V_O}$	Differential Output Voltage, V_A, B	$R_L = \infty$	$V_{IN} = 2.0\text{V}$		3.6	6.0	Volts
			$V_{IN} = 0.8\text{V}$		-3.6	-6.0	Volts
$\frac{V_T}{V_T}$	Differential Output Voltage, V_A, B	$R_L = 100\Omega$	$V_{IN} = 2.0\text{V}$	2.0	2.4		Volts
			$V_{IN} = 0.8\text{V}$	-2.0	-2.4		Volts
$V_{OS}, \overline{V_{OS}}$	Common Mode Offset Voltage	$R_L = 100\Omega$		2.5	3.0	Volts	
$ \overline{V_T} - \overline{V_T} $	Difference in Differential Output Voltage	$R_L = 100\Omega$		0.005	0.4	Volts	
$ \overline{V_{OS}} - \overline{V_{OS}} $	Difference in Common Mode Offset Voltage	$R_L = 100\Omega$		0.005	0.4	Volts	
V_{SS}	$ \overline{V_T} - \overline{V_T} $	$R_L = 100\Omega$	4.0	4.8		Volts	
V_{CMR}	Output Voltage Common Mode Range	$\overline{V_{ENABLE}} = 2.4\text{V}$	±10			Volts	
I_{XA}	Output Leakage Current	$V_{CC} = 0\text{V}$	$V_{CMR} = 10\text{V}$			100	μA
I_{XB}			$V_{CMR} = -10\text{V}$			-100	μA
I_{OX}	Off State (High Impedance) Output Current	$V_{CC} = \text{MAX.}$	$V_{CMR} \leq 10\text{V}$			100	μA
			$V_{CMR} \geq -10\text{V}$			-100	μA
I_{SA}, I_{SB}	Output Short Circuit Current	$V_{IN} = 2.4\text{V}$	$V_{OA} = 6.0\text{V}$		80	150	mA
			$V_{OB} = 0\text{V}$		-80	-150	mA
		$V_{IN} = 0.4\text{V}$	$V_{OA} = 0\text{V}$		-80	-150	mA
			$V_{OB} = 6.0\text{V}$		80	150	mA
I_{CC}	Supply Current			18	30	mA	
V_{IH}	High Level Input Voltage		2.0			Volts	
V_{IL}	Low Level Input Voltage				0.8	Volts	
I_{IH}	High Level Input Current	$V_{IN} = 2.4\text{V}$		1.0	40	μA	
		$V_{IN} \leq 15\text{V}$		10	100	μA	
I_{IL}	Low Level Input Current	$V_{IN} = 0.4\text{V}$		-30	-200	μA	
V_I	Input Clamp Voltage	$I_{IN} = -12\text{mA}$			-1.5	Volts	

AC CHARACTERISTICSEIA RS-422 Connection, $V_{CC} = 5.0\text{V}$, $V_{EE} = \text{GND}$, Mode = 0.4V, $T_A = 25^\circ\text{C}$

Parameters	Description	Test Conditions	Min.	Typ. (Note 1)	Max.	Units
t_r	Differential Output Rise Time	Fig. 2, $R_L = 100\Omega$, $C_L = 500\text{pF}$		120	200	ns
t_f	Differential Output Fall Time	Fig. 2, $R_L = 100\Omega$, $C_L = 500\text{pF}$		120	200	ns
t_{PDH}	Output Propagation Delay	Fig. 2, $R_L = 100\Omega$, $C_L = 500\text{pF}$		120	200	ns
t_{PDL}	Output Propagation Delay	Fig. 2, $R_L = 100\Omega$, $C_L = 500\text{pF}$		120	200	ns

- Notes: 1. Typical limits are at $V_{CC} = 5.0\text{V}$, $V_{EE} = \text{GND}$, 25°C ambient and maximum loading.
 2. Symbols and definitions correspond to EIA RS-422 where applicable.
 3. R_L connected between each output and its complement.

Am26LS30

ELECTRICAL CHARACTERISTICS over the operating temperature range

The following conditions apply unless otherwise specified:

Am26LS30XM (MIL) $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$, $V_{EE} = -5.0\text{V} \pm 10\%$

Am26LS30XC (COM'L) $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$, $V_{EE} = -5.0\text{V} \pm 5\%$

RS-423 Connection, Mode Voltage $\geq 2.0\text{V}$

DC CHARACTERISTICS over the operating temperature range (Notes 1 and 2)

Parameters	Description	Test Conditions	Min.	Typ. (Note 1)	Max.	Units	
$\frac{V_O}{V_O}$	Output Voltage	$R_L = \infty$	$V_{IN} = 2.4\text{V}$	4.0	4.4	6.0	Volts
			$V_{IN} = 0.4\text{V}$	-4.0	-4.4	-6.0	Volts
$\frac{V_T}{V_T}$	Output Voltage	$R_L = 450\Omega$	$V_{IN} = 2.4\text{V}$	3.6	4.1		Volts
			$V_{IN} = 0.4\text{V}$	-3.6	-4.1		Volts
$ \overline{V_T} - \underline{V_T} $	Output Unbalance	$ V_{CC} = V_{EE} $, $R_L = 450\Omega$		0.02	0.4	Volts	
I_{X+}	Output Leakage Power Off	$V_{CC} = V_{EE} = 0\text{V}$	$V_O = 6.0\text{V}$		2.0	100	μA
I_{X-}			$V_O = -6.0\text{V}$		-2.0	-100	μA
I_{S+}	Output Short Circuit Current	$V_O = 0\text{V}$	$V_{IN} = 2.4\text{V}$		-80	-150	mA
I_{S-}			$V_{IN} = 0.4\text{V}$		80	150	mA
I_{Slew}	Slew Control Current	$V_{SLEW} = V_{EE} + 0.9\text{V}$		± 140		μA	
I_{CC}	Positive Supply Current	$V_{IN} = 2.4\text{V}$, $R_L = \infty$		18	30	mA	
I_{EE}	Negative Supply Current	$V_{IN} = 0.4\text{V}$, $R_L = \infty$		-10	-22	mA	
V_{IH}	High Level Input Voltage		2.0			Volts	
V_{IL}	Low Level Input Voltage				0.8	Volts	
I_{IH}	High Level Input Current	$V_{IN} = 2.4\text{V}$		1.0	40	μA	
		$V_{IN} \leq 15\text{V}$		10	100	μA	
I_{IL}	Low Level Input Current	$V_{IN} = 0.4\text{V}$		-30	-200	μA	
V_I	Input Clamp Voltage	$I_{IN} = -12\text{mA}$			-1.5	Volts	

AC CHARACTERISTICS

RS-423 Connection, $V_{CC} = 5.0\text{V}$, $V_{EE} = -5.0\text{V}$, Mode = 2.4V, $T_A = 25^\circ\text{C}$

Parameters	Description	Test Conditions	Min.	Typ. (Note 1)	Max.	Units	
Sr+	Positive Slew Rate	Fig. 1, $R_L = 450\Omega$, $C_L = 500\text{pF}$	$C_C = 50\text{pF}$		3.0		μs
			$C_C = 0$		120	300	ns
Sr-	Negative Slew Rate	Fig. 1, $R_L = 450\Omega$, $C_L = 500\text{pF}$	$C_C = 50\text{pF}$		3.0		μs
			$C_C = 0$		120	300	ns
Src	Slew Rate Coefficient	Fig. 1, $R_L = 450\Omega$, $C_L = 500\text{pF}$.06		$\mu\text{s/pF}$	
tpDH	Output Propagation Delay	Fig. 1, $R_L = 450\Omega$, $C_L = 500\text{pF}$, $C_C = 0$		180	300	ns	
tpDL	Output Propagation Delay	Fig. 1, $R_L = 450\Omega$, $C_L = 500\text{pF}$, $C_C = 0$		180	300	ns	

Notes: 1. Typical limits are at $V_{CC} = 5.0\text{V}$, $V_{EE} = -5.0\text{V}$, 25°C ambient and maximum loading.

2. Symbols and definitions correspond to EIA RS-423 where applicable.

Am26LS31

Quad High Speed Differential Line Driver

DISTINCTIVE CHARACTERISTICS

- Output skew — 2.0ns typical
- Input to output delay — 12ns
- Operation from single +5V supply
- 16-pin hermetic and molded DIP package
- Outputs won't load line when $V_{CC} = 0$
- Four line drivers in one package for maximum package density
- Output short-circuit protection
- Complementary outputs
- Meets the requirements of EIA standard RS-422
- High output drive capability for 100Ω terminated transmission lines
- Available in military and commercial temperature range
- Advanced low-power Schottky processing
- 100% reliability assurance screening to MIL-STD-883 requirements

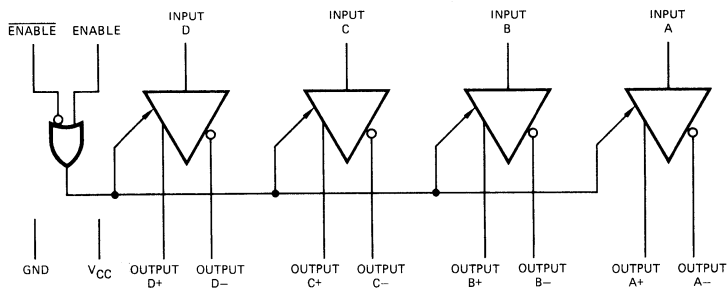
FUNCTIONAL DESCRIPTION

The Am26LS31 is a quad differential line driver, designed for digital data transmission over balanced lines. The Am26LS31 meets all the requirements of EIA standard RS-422 and federal standard 1020. Is is designed to provide unipolar differential drive to twisted-pair or parallel-wire transmission lines.

The circuit provides an enable and disable function common to all four drivers. The Am26LS31 features 3-state outputs and logical OR-ed complementary enable inputs. The inputs are all LS compatible and are all one unit load.

The Am26LS31 is constructed using advanced low-power Schottky processing.

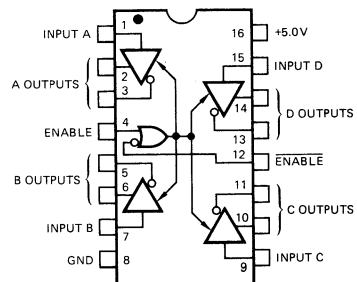
LOGIC DIAGRAM



ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Hermetic DIP	-55°C to +125°C	AM26LS31DM
Flat Pak	-55°C to +125°C	AM26LS31FM
Dice	-55°C to +125°C	AM26LS31XM
Hermetic DIP	0°C to +70°C	AM26LS31DC
Molded DIP	0°C to +70°C	AM26LS31PC
Dice	0°C to +70°C	AM26LS31XC

CONNECTION DIAGRAM (Top View)



Note: Pin 1 is marked for orientation.

ABSOLUTE MAXIMUM RATINGS (Above which the useful life may be impaired)

Supply Voltage	7.0V
Input Voltage	7.0V
Output Voltage	5.5V
Storage Temperature Range	-65°C to +150°C

ELECTRICAL CHARACTERISTICS over the operating temperature range

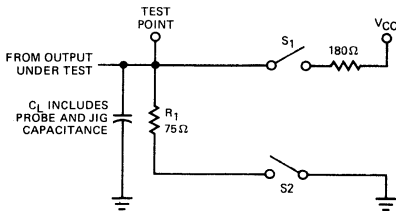
The following conditions apply unless otherwise specified:

Am26LS31XM (MIL)	T _A = -55°C to +125°C	V _{CC} = 5V ± 10%
Am26LS31XC (COM'L)	T _A = 0°C to +70°C	V _{CC} = 5V ± 5%

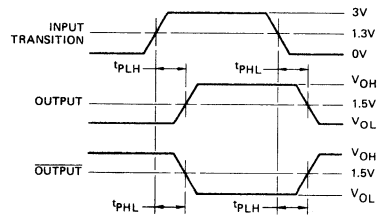
Parameters	Description	Test Conditions	Min.	Typ. (Note 1)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = Min., I _{OH} = -20mA	2.5	3.2		Volts	
V _{OL}	Output LOW Voltage	V _{CC} = Min., I _{OL} = 20mA		0.32	0.5	Volts	
V _{IH}	Input HIGH Voltage	V _{CC} = Min.	2.0			Volts	
V _{IL}	Input LOW Voltage	V _{CC} = Max.			0.8	Volts	
I _{IL}	Input LOW Current	V _{CC} = Max., V _{IN} = 0.4V		-0.20	-0.36	mA	
I _{IH}	Input HIGH Current	V _{CC} = Max., V _{IN} = 2.7V		0.5	20	μA	
I _I	Input Reverse Current	V _{CC} = Max., V _{IN} = 7.0V		0.001	0.1	mA	
I _O	Off-State (High Impedance) Output Current	V _{CC} = Max.		V _O = 5.5V	0.5	20	μA
				V _O = 0.5V	0.5	-20	
V _I	Input Clamp Voltage	V _{CC} = Min., I _{IN} = 18mA		-0.8	-1.5	Volts	
I _{SC}	Output Short Circuit Current	V _{CC} = Max.	-30	-60	-150	mA	
I _{CC}	Power Supply Current	V _{CC} = Max., all outputs disabled		60	80	mA	
t _{PLH}	Input to Output	V _{CC} = 5.0V, T _A = 25°C, Load = Note 2		12	20	ns	
t _{PHL}	Input to Output	V _{CC} = 5.0V, T _A = 25°C, Load = Note 2		12	20	ns	
SKEW	Output to Output	V _{CC} = 5.0V, T _A = 25°C, Load = Note 2		2.0	6.0	ns	
t _{LZ}	Enable to Output	V _{CC} = 5.0V, T _A = 25°C, C _L = 10pF		23	35	ns	
t _{HZ}	Enable to Output	V _{CC} = 5.0V, T _A = 25°C, C _L = 10pF		17	30	ns	
t _{ZL}	Enable to Output	V _{CC} = 5.0V, T _A = 25°C, Load = Note 2		35	45	ns	
t _{ZH}	Enable to Output	V _{CC} = 5.0V, T _A = 25°C, Load = Note 2		30	40	ns	

- Notes: 1. All typical values are V_{CC} = 5.0V, T_A = 25°C.
 2. C_L = 30pF, V_{IN} = 1.3V to V_{OUT} = 1.3V, V_{PULSE} = 0V to +3.0V. See Below.

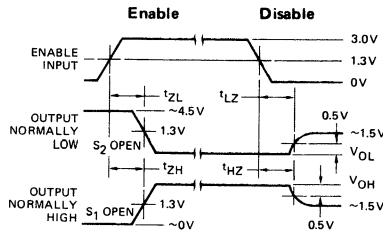
AC LOAD TEST CIRCUIT FOR THREE-STATE OUTPUTS



PROPAGATION DELAY (Notes 1 and 3)

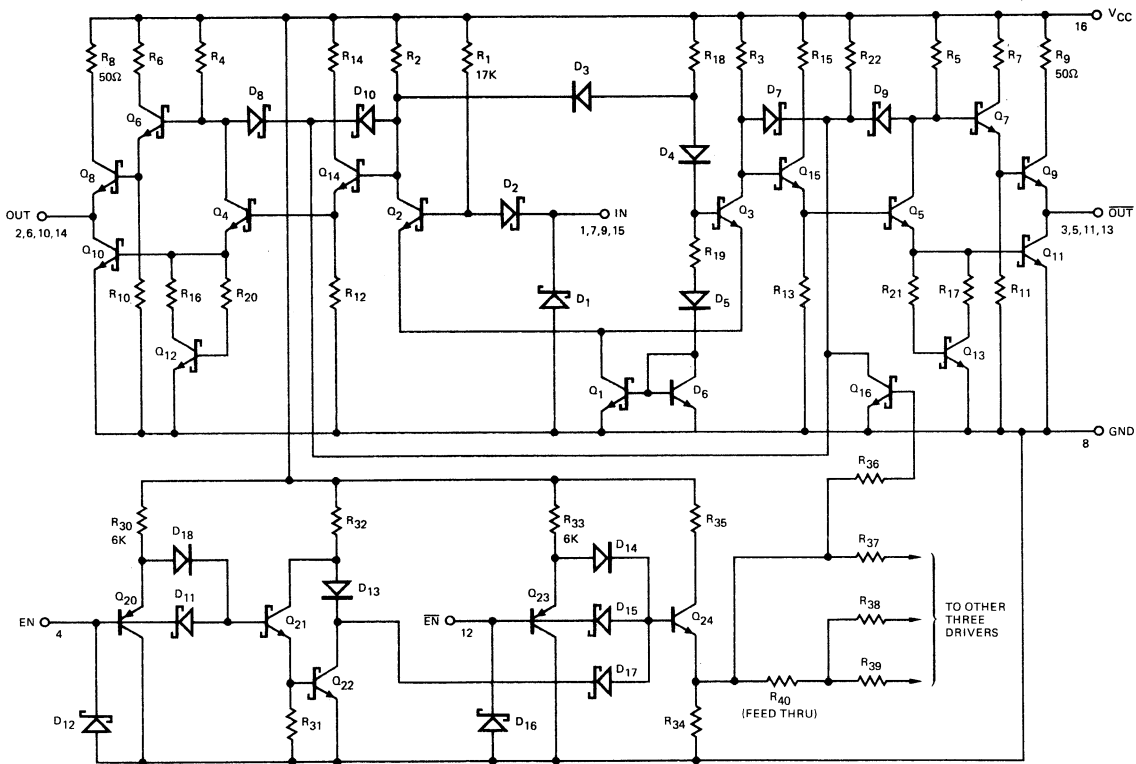


ENABLE AND DISABLE TIMES (Notes 2 and 3)



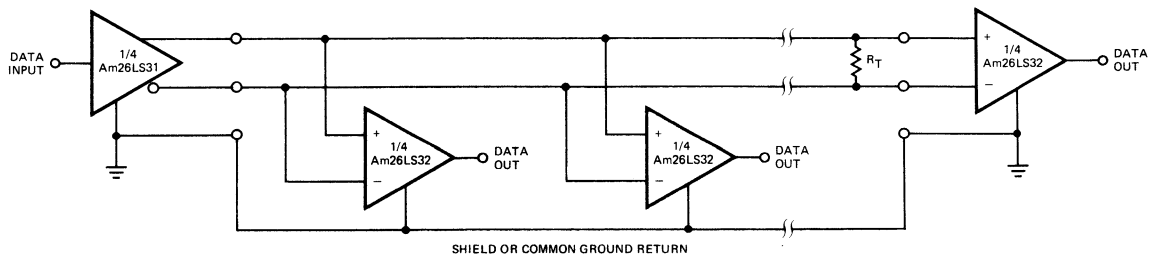
- Notes: 1. Diagram shown for Enable LOW.
 2. S₁ and S₂ of Load Circuit are closed except where shown.
 3. Pulse Generator for All Pulses: Rate ≤ 1.0MHz; Z₀ = 50Ω; t_r ≤ 15ns; t_f ≤ 6.0ns.

EQUIVALENT CIRCUIT (1/4 Am26LS31)

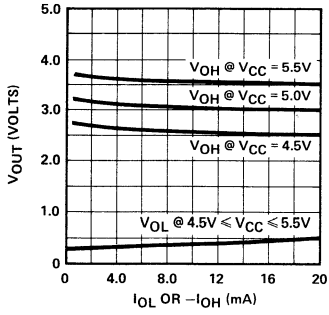


3

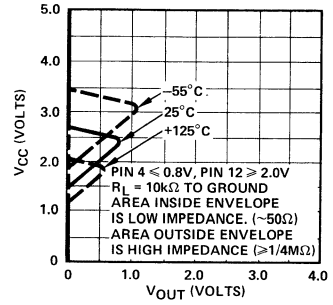
TYPICAL APPLICATION



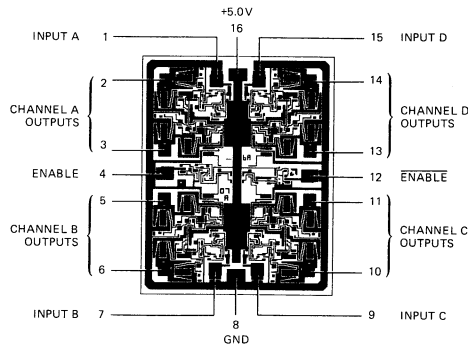
Guaranteed V_{OH} and V_{OL}
($T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$)



V_{OUT} Versus V_{CC}



Metallization and Pad Layout



DIE SIZE 0.067" X 0.084"

Am26LS32 • Am26LS33

Quad Differential Line Receivers

DISTINCTIVE CHARACTERISTICS

- Input voltage range of 15V (differential or common mode) on Am26LS33; 7V (differential or common mode) on Am26LS32
- $\pm 0.2V$ sensitivity over the input voltage range on Am26LS32; $\pm 0.5V$ sensitivity on Am26LS33
- The Am26LS32 meets all the requirements of RS-422 and RS-423
- 6k minimum input impedance
- 30mV input hysteresis
- Operation from single +5V supply
- 16-pin hermetic and molded DIP package
- Fail safe input-output relationship. Output always high when inputs are open.
- Three-state drive, with choice of complementary output enables, for receiving directly onto a data bus.
- Propagation delay 17ns typical
- Available in military and commercial temperature range
- Advanced low-power Schottky processing
- 100% reliability assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am26LS32 is a quad line receiver designed to meet the requirements of RS-422 and RS-423, and Federal Standards 1020 and 1030 for balanced and unbalanced digital data transmission.

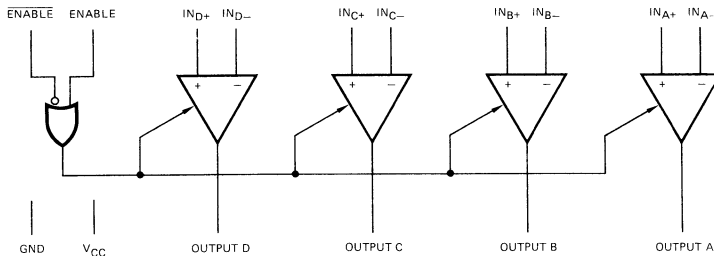
The Am26LS32 features an input sensitivity of 200mV over the input voltage range* of $\pm 7V$.

The Am26LS33 features an input sensitivity of 500mV over the input voltage range of $\pm 15V$.

The Am26LS32 and Am26LS33 provide an enable and disable function common to all four receivers. Both parts feature 3-state outputs with 8mA sink capability and incorporate a fail safe input-output relationship which keeps the outputs high when the inputs are open.

The Am26LS32 and Am26LS33 are constructed using Advanced Low-Power Schottky processing.

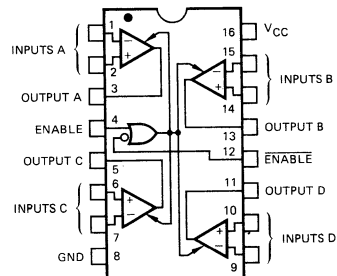
LOGIC DIAGRAM



ORDERING INFORMATION

Package Type	Temperature Range	Am26LS32	Am26LS33
		Order Number	Order Number
Hermetic DIP	$-55^{\circ}C$ to $+125^{\circ}C$	AM26LS32DM	AM26LS33DM
Flat Pak	$-55^{\circ}C$ to $+125^{\circ}C$	AM26LS32FM	AM26LS33FM
Dice	$-55^{\circ}C$ to $+125^{\circ}C$	AM26LS32XM	AM26LS33XM
Hermetic DIP	$0^{\circ}C$ to $+70^{\circ}C$	AM26LS32DC	AM26LS33DC
Molded DIP	$0^{\circ}C$ to $+70^{\circ}C$	AM26LS32PC	AM26LS33PC
Dice	$0^{\circ}C$ to $+70^{\circ}C$	AM26LS32XC	AM26LS33XC

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

ABSOLUTE MAXIMUM RATINGS (Above which the useful life may be impaired)

Supply Voltage	7.0V
Common Mode Range	±25V
Differential Input Voltage	±25V
Enable Voltage	7.0V
Output Sink Current	50mA
Storage Temperature Range	-65°C to +165°C

ELECTRICAL CHARACTERISTICS Over the operating temperature range

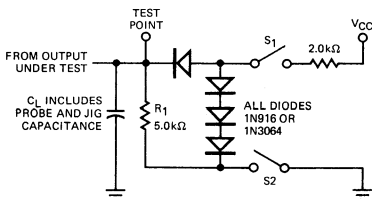
The following conditions apply unless otherwise specified:

Am26LS32XM, Am26LS33XM (MIL) $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 10\%$
 Am26LS32XC, Am26LS33XC (COM'L) $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC} = 5.0\text{V} \pm 5\%$

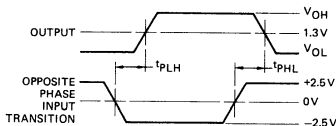
Parameters	Description	Test Conditions	Min.	Typ. (Note 1)	Max.	Units
V_{TH}	Differential Input Voltage	$V_{OUT} = V_{OL}$ or V_{OH}				
		Am26LS32, $-7\text{V} \leq V_{CM} \leq +7\text{V}$	0.2	0.06	0.2	Volts
	Am26LS33, $-15\text{V} \leq V_{CM} \leq +15\text{V}$	0.5	0.12	0.5		
R_{IN}	Input Resistance	$-15\text{V} \leq V_{CM} \leq +15\text{V}$ (One input AC ground)	6.0k	8.5k		Ω
I_{IN}	Input Current (Under Test)	$V_{IN} = +15\text{V}$, Other Input $-15\text{V} \leq V_{IN} \leq +15\text{V}$			2.3	mA
I_{IN}	Input Current (Under Test)	$V_{IN} = -15\text{V}$, Other Input $-15\text{V} \leq V_{IN} \leq +15\text{V}$			-2.8	mA
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{Min.}, \Delta V_{IN} = +1.0\text{V}$ $\overline{V_{ENABLE}} = 0.8\text{V}, I_{OH} = -440\mu\text{A}$	COM'L	2.7	3.4	Volts
		MIL	2.5	3.4		
V_{OL}	Output LOW Voltage	$V_{CC} = \text{Min.}, \Delta V_{IN} = -1.0\text{V}$ $\overline{V_{ENABLE}} = 0.8\text{V}$	$I_{OL} = 4.0\text{mA}$		0.4	Volts
		$I_{OL} = 8.0\text{mA}$		0.45		
V_{IL}	Enable LOW Voltage				0.8	Volts
V_{IH}	Enable HIGH Voltage		2.0			Volts
V_I	Enable Clamp Voltage	$V_{CC} = \text{Min.}, I_{IN} = -18\text{mA}$			-1.5	Volts
I_O	Off-State (High Impedance) Output Current	$V_{CC} = \text{Max.}$	$V_O = 2.4\text{V}$		20	μA
			$V_O = 0.4\text{V}$		-20	
I_{IL}	Enable LOW Current	$V_{IN} = 0.4\text{V}$		-0.2	-0.36	mA
I_{IH}	Enable HIGH Current	$V_{IN} = 2.7\text{V}$		0.5	20	μA
I_I	Enable Input High Current	$V_{IN} = 5.5\text{V}$		1	100	μA
I_{SC}	Output Short Circuit Current	$V_O = 0\text{V}, V_{CC} = \text{Max.}, \Delta V_{IN} = +1.0\text{V}$	-15	-50	-85	mA
I_{CC}	Power Supply Current	$V_{CC} = \text{Max.}, \text{All } V_{IN} = \text{GND}, \text{Outputs Disabled}$		52	70	mA
V_{HYST}	Input Hysteresis	$T_A = 25^\circ\text{C}, V_{CC} = 5.0\text{V}, V_{CM} = 0\text{V}$		30		mV
t_{PLH}	Input to Output	$T_A = 25^\circ\text{C}, V_{CC} = 5.0\text{V}, C_L = 15\text{pF}$, see test cond. below		17	25	ns
t_{PHL}	Input to Output	$T_A = 25^\circ\text{C}, V_{CC} = 5.0\text{V}, C_L = 15\text{pF}$, see test cond. below		17	25	ns
t_{LZ}	Enable to Output	$T_A = 25^\circ\text{C}, V_{CC} = 5.0\text{V}, C_L = 5\text{pF}$, see test cond. below		20	30	ns
t_{HZ}	Enable to Output	$T_A = 25^\circ\text{C}, V_{CC} = 5.0\text{V}, C_L = 5\text{pF}$, see test cond. below		15	22	ns
t_{ZL}	Enable to Output	$T_A = 25^\circ\text{C}, V_{CC} = 5.0\text{V}, C_L = 15\text{pF}$, see test cond. below		15	22	ns
t_{ZH}	Enable to Output	$T_A = 25^\circ\text{C}, V_{CC} = 5.0\text{V}, C_L = 15\text{pF}$, see test cond. below		15	22	ns

Note: 1. All typical values are $V_{CC} = 5.0\text{V}, T_A = 25^\circ\text{C}$.

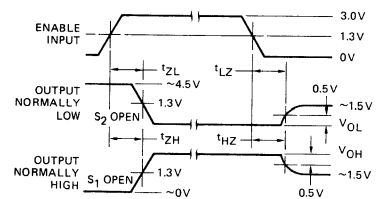
LOAD TEST CIRCUIT FOR THREE-STATE OUTPUTS



PROPAGATION DELAY (Notes 1 and 3)

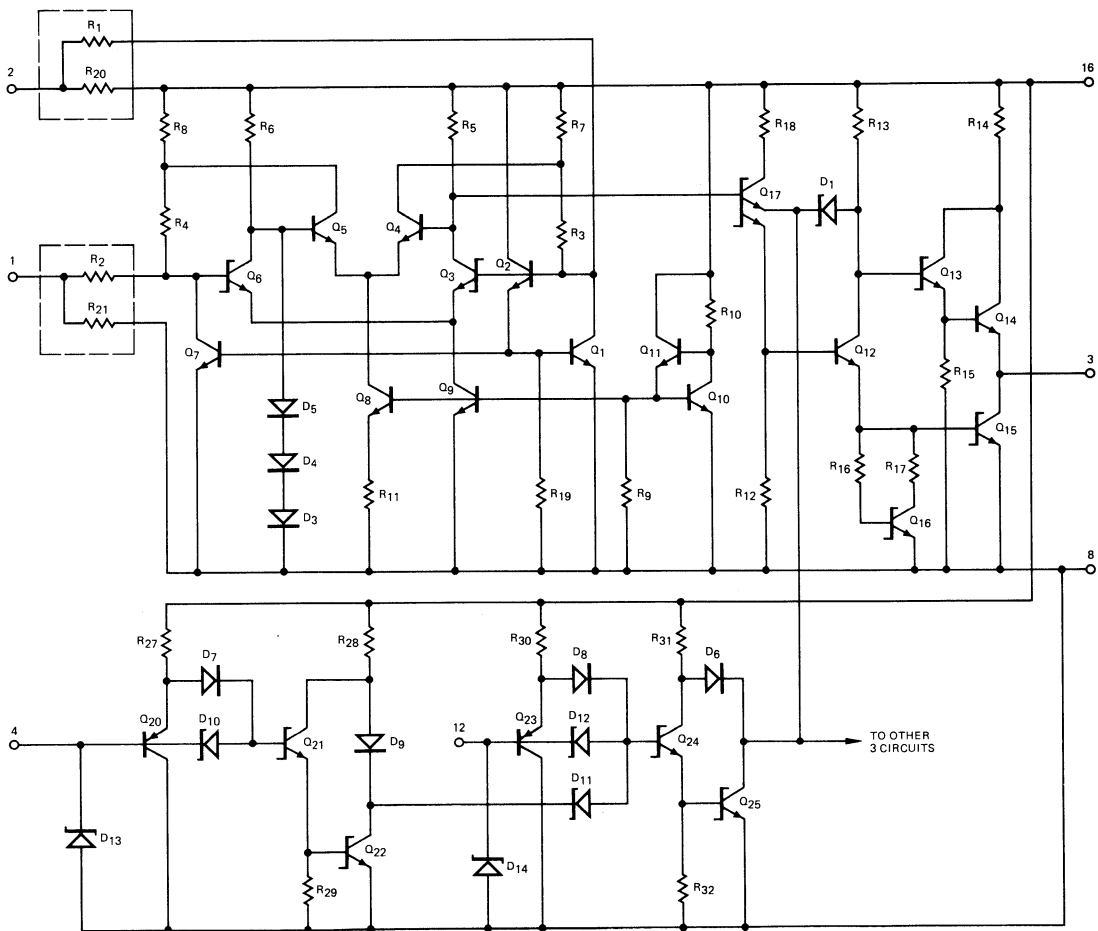


ENABLE AND DISABLE TIMES (Notes 2 and 3)



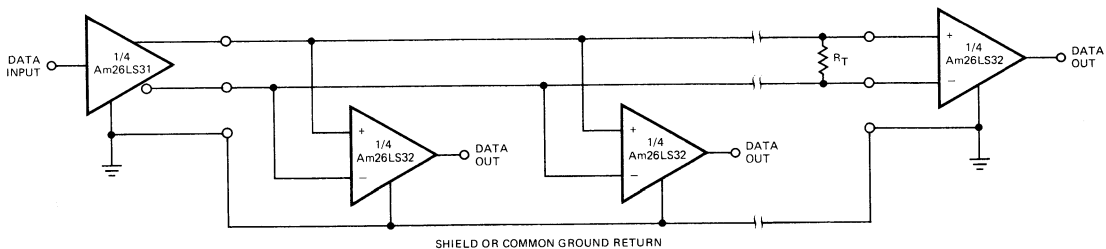
- Notes:
1. Diagram shown for Enable LOW.
 2. S_1 and S_2 of Load Circuit are closed except where shown.
 3. Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $Z_O = 50\Omega$; $t_r \leq 15\text{ns}$; $t_f \leq 6.0\text{ns}$.

EQUIVALENT CIRCUIT (1/4 Am26LS32 OR Am26LS33)

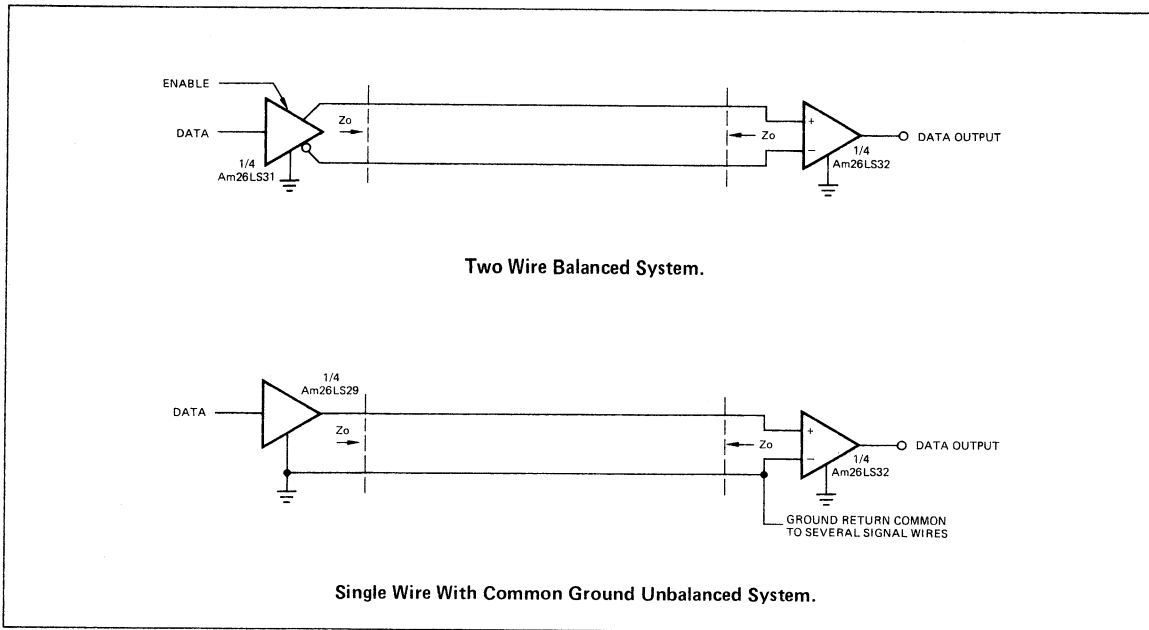


Note: R₃ and R₄ value for Am26LS32 is 2 times Am26LS33 value.

TYPICAL APPLICATION



3



LINE TERMINATION

It is important in a digital communication system to have the minimum amount of noise generated by undesired reflections at the driver and receiver. There are numerous ways of matching to the line. The line can be matched at the driver, at the receiver or both, each method has advantages and disadvantages. Generally for any but the longest lines it is sufficient to match at one place, and only when there are discontinuities in the line, party line operation, or lack of a reasonable match at the opposite end of the line is the extra hardware of matching at both ends justified. The majority of transmission lines have fairly low characteristic impedances (in the range of 50 to 200 ohms) and the currents involved for a reasonable voltage swing are quite large. It is more difficult to couple noise into this low impedance, but it is also more difficult to drive, and line drivers must have the ability to supply large currents.

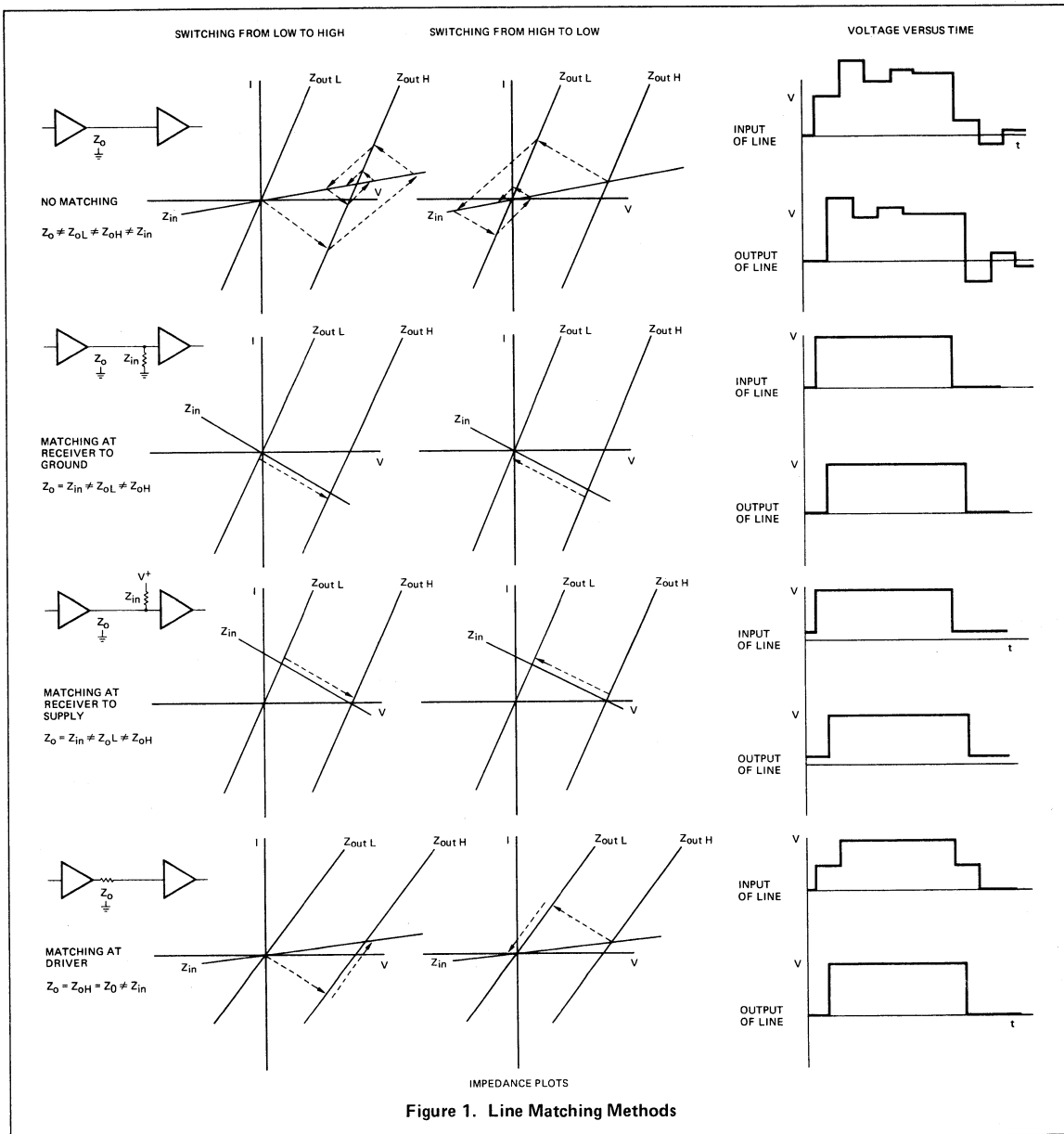
Various matching techniques that can be employed are shown in Figure 1. These impedance charts are useful in showing what happens to wave fronts traveling down a line, when the line delay is longer than the wave front transition. The DC input characteristic of the receiver, including any external components, is plotted on the V-I graph together with the output characteristic of the driver, including any external components used at the driving end. There are always quiescent points — points where the driver and receiver characteristics cross. These points represent the DC voltage/current conditions, which must eventually be satisfied. To determine the effect of switching from one quiescent point to the other, a line with a slope equal to the characteristic impedance of the transmission line is plotted, starting at the initial quiescent point and ending at the applicable output impedance characteristic. The point of intersection gives the voltage and current at the output of the driver (and the input of the transmission line immediately after the driver switched states). From this point a line having an equal but opposite slope is drawn to the input characteristic and, at the intersection shows the voltage/current conditions of the wave front at the input of the receiver. This procedure is repeated to the output characteristic and so on at each intersection of the characteristic, the voltage/current relationship for a particular reflection is given. The resulting time/

voltage relationships for the traveling wavefront at the two ends of the transmission line are shown alongside.

From the graphs several important features can be seen. If the line is not matched at either end considerable transient voltage swings can occur. In fact if the input and output characteristics are at right angles to one another, the reflections continue for an infinite time if the line is assumed to have zero loss. Most lines have extremely low losses, and, therefore, a very undesirable situation exists if the line is not matched at either end.

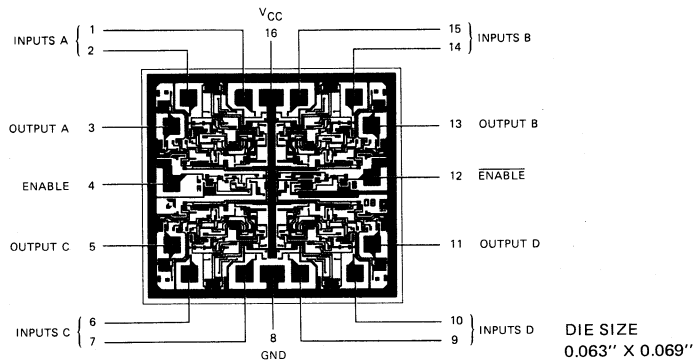
If the line is matched at the receiver, a voltage wave of constant amplitude travels down the line and is absorbed at the termination. Note whether the line is terminated to ground or to the power supply the system consumes DC power, either in the HIGH logic level or in the LOW logic level. In order to reduce the power dissipation, a blocking capacitor can be used in series with the receiver termination. The capacitor can be chosen to look like a short circuit to the voltage wavefront but stop DC (current) flow. Since the capacitor must be charged and discharged through the line, the data rate is reduced, when this technique is employed.

If the line is matched with a series resistor at the driver, then the line input initially rises to one half the final voltage. This wave front travels down the line and is reflected at the receiver. When the reflection reaches the driver the voltage at the driver rises to its final amplitude. The receiver, however, sees one transition from the initial to the final amplitude. When the driver switches from HIGH to LOW a similar situation occurs, in which the input of the line sees at first a step to one half the final value and, two line delays later, the final LOW condition. This back matching mode of operation consumes no DC power if the input impedance of the receiver is infinite. The advantage of the method is that if the input impedance of the receiver is high, very little power is dissipated and current only flows during the transition time, which is twice the line delay time. If back matching is used in a balanced system the terminating series resistance must be divided into two equal resistances with resistors inserted in series with each wire in order to maintain a balanced system.



3

Metallization and Pad Layout



USE OF THE Am26LS30, 31 AND 32 QUAD DRIVER/RECEIVER FAMILY IN EIA RS-422 and 423 APPLICATIONS

By David A. Laws and Roy J. Levy

INTRODUCTION

Today's high-performance data processing systems demand significantly faster data communications rates than are possible with the EIA RS-232C specifications in use for the past ten years.

Two new standards prepared by the Electronic Industries Association address this need. EIA RS-423 is an unbalanced, bipolar voltage specification designed to interface with RS-232C, while greatly enhancing its operation. It permits the communication of digital information over distances of up to 2000 feet and at data rates of up to 300 Kilobaud. EIA RS-422 is a balanced voltage digital interface for communication of digital data over distances of 4000 feet or data rates of up to 10 megabaud.

Advanced Micro Devices has developed a family of monolithic Low-power Schottky quad line drivers and receivers to meet the requirements of these specifications.

The Am26LS29 and 30 line drivers and the Am26LS32 receiver meet all requirements of RS-423 while the Am26LS31 differential line driver and the Am26LS32 receiver meet the requirements of RS-422.

A second receiver element, the Am26LS33 is available for use in high common mode noise environments, exceeding the common mode voltage requirements of RS-422 and RS-423.

This application note reviews the use of these devices in implementing the new standards. Emphasis is given to the EIA RS-422 balanced interface.

EIA STANDARD SPECIFICATIONS

Two basic forms of operation are available for transmission of digital data over interconnecting lines. These are the single ended and differential techniques.

The single-ended form uses a single conductor to carry the signal with the voltage referenced to a single return conductor. This may also be the common return for other signal conductors. Figure 1a.

The single-ended form is the simplest way to send data as it requires only one signal line per circuit. This simplicity, however, is often offset by the inability of this form to allow discrimination between a valid signal produced by the driver, and the sum of the driver signal plus externally induced noise signals.

A solution to some of the problems inherent in the single-ended form of operation is offered by the differential form of operation. Figure 1b. This consists of a differential driver (essentially two single-ended drivers with one driver always producing the complementary output signal level to the other driver), a twisted pair transmission line and a differential line receiver. The driver signal appears as a differential voltage to the line receiver, while the noise signals appear as a common mode signal. The two signals, therefore, can be discriminated by a line receiver with a sufficient common mode voltage operating range.

The Electronic Industries Association, EIA, has defined a number of specifications standardizing the interface between data terminal equipment and data circuit terminating equipment based on both single-ended and differential operation.

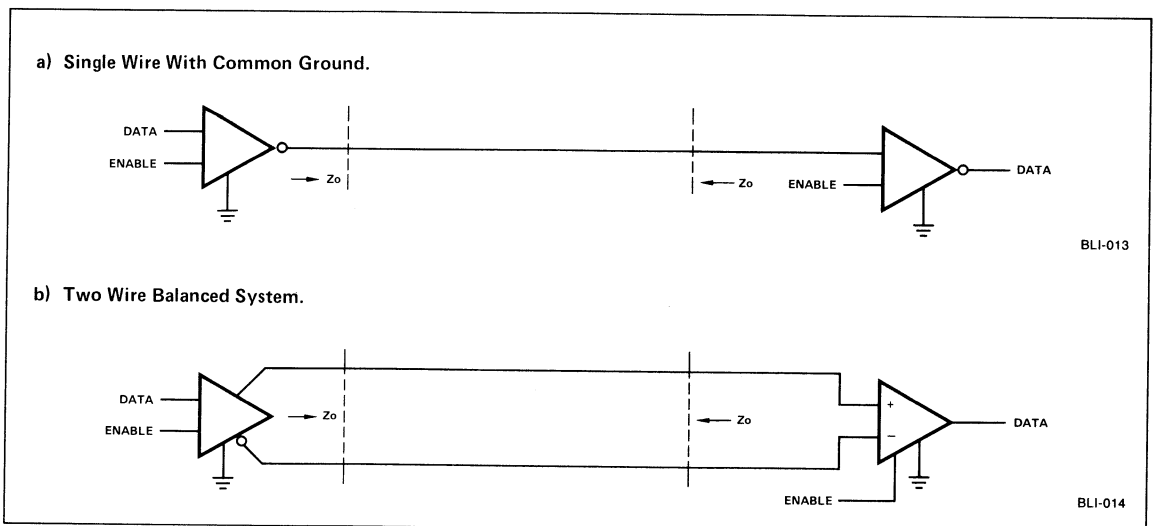


Figure 1. Data Communication Techniques.

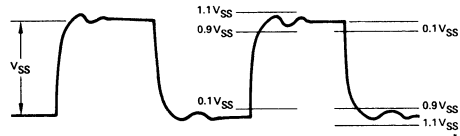
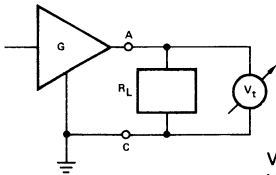
The most widely used standard for interfacing between data terminal equipment and data communications equipment today, is EIA RS-232C, issued in August 1969. The RS-232C electrical interface is a single-ended, bipolar-voltage, unterminated circuit. This specification is for serial binary data interchange over short distances (up to 50 feet) at low rates (up to 20 Kilobaud). It is a protocol standard as well as an electrical standard, specifying hand shaking signals and functions between terminal and the communications equipment. As already noted, single-ended circuits are susceptible to all forms of electromagnetic interference. Noise and cross talk susceptibility are proportional to length and bandwidth. RS-232C places restrictions on both. It limits slew rate of the drivers ($30V/\mu s$) to control radiated emission on neighboring circuits and allows bandwidth limiting on the receivers to reduce susceptibility to cross talk. The length and slew rate limits can adequately control reflections on unterminated lines, and the length and bandwidth limits are more than adequate to reduce susceptibility to noise.

Like EIA RS-232C, the new EIA RS-423 is also a single-ended, bipolar-voltage unterminated circuit. It extends the distance and data rate capabilities of this technique to distances of up to 4000 feet at data rates of 3000 baud, or at higher rates of up to 300 Kilobaud over a maximum distance of 40 feet.

EIA RS-422 is a differential, balanced voltage interface capable of significantly higher data rates over longer distances. It can accommodate rates of 100 Kilobaud over a distance of 4000 feet or rates of up to 10 megabaud. These performance improvements stem from the advantages of a balanced configuration which is isolated from ground noise currents. It is also immune to fluctuating voltage potentials between system ground references and to common mode electromagnetic interference. Figure 2 compares the driver output waveforms for the three EIA standard configurations, while Table I compares the key characteristics required by drivers and receivers intended for these applications. Since RS-232C has been in use for many years, RS-422 and 423 parameter values have been selected to facilitate an orderly transition from existing designs to new equipment.

3

a) EIA RS-232C Generator Output.



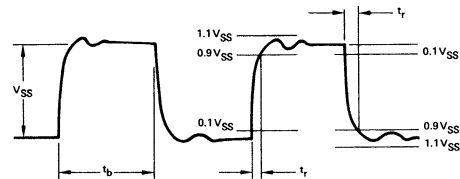
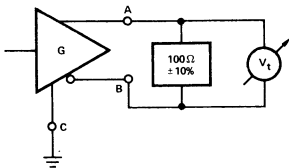
$$V_{SS} = |V_t - \bar{V}_t|$$

V_{SS} = Difference in steady state voltages

$$R_L = 3K\Omega \text{ to } 7K\Omega$$

$$V_{SS \text{ min.}} = \pm 5V; V_{SS \text{ max.}} = \pm 25V$$

b) EIA RS-422 Generator Output.



t_D = Time duration of the unit interval at the applicable modulation rate

$$t_r \leq 0.1 t_D \text{ when } t_D \geq 200ns$$

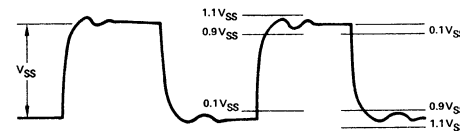
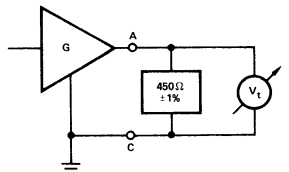
$$t_r \leq 20ns \text{ when } t_D < 200ns$$

V_{SS} = Difference in steady state voltages

$$V_{SS} = |V_t - \bar{V}_t|$$

$$V_{SS \text{ min.}} = 2V; V_{SS \text{ max.}} = 6V$$

c) EIA RS-423 Generator Output.



$$V_{SS} = |V_t - \bar{V}_t|$$

V_{SS} = Difference in steady state voltages

$$V_{SS \text{ min.}} = \pm 3.6V; V_{SS \text{ max.}} = \pm 6V$$

Figure 2. Driver Output Waveforms.

TABLE I
KEY PARAMETERS OF EIA SPECIFICATIONS

Characteristics	EIA RS-232C	EIA RS-423	EIA RS-422	Units
Form of Operation	Single Ended	Single Ended	Differential	
Max. cable length	50	2000	4000	Feet
Max. data rate	20K	300K	10M	Baud
Driver output voltage, open circuit*	±25	±6	6 volts between outputs	Volts (Max.)
Driver output voltage, Loaded output*	±5 to ±15	±3.6	2 volts between outputs	Volts (Min.)
Driver output resistance power off	$R_o = 300\Omega$	100 μ A between -6 to +6V	100 μ A between +6 and -25V	Min.
Driver output short circuit current I_{SC}	±500	±150	±150	mA (Max.)
Driver output slew rate	30 V/ μ sec Max.	Slew rate must be controlled based upon cable length and modulation rate	No control necessary	
Receiver input resistance R_{in}	3K to 7K	≥4K	≥4K	Ω
Receiver input thresholds	-3 to +3	-0.2 to +0.2	-0.2 to +0.2	Volts (Max.)
Receiver input voltage	-25 to +25	-12 to +12	-12 to +12	Volts (Max.)

* ± indicates polarity switched output.

INTEGRATED CIRCUIT CHARACTERISTICS

Most semiconductor manufacturers offer integrated circuits designed to satisfy the old RS-232C standard. A number of them have designs in progress to meet the new EIA specifications. Products available from Advanced Micro Devices to meet these needs are shown in Table II.

The Am26LS29, 30, 31 and 32 are a family of quad drivers and receivers designed specifically to meet the new EIA standards. These products utilize Low-Power Schottky technology to incorporate four drivers or four receivers, together with control logic, in the standard 16-pin package outlines.

The Am26LS29/30 and the Am26LS32 are driver and receiver pairs designed to implement the single-ended EIA RS-423 standard. The Am26LS31 is a differential line driver designed for use with the Am26LS32 receiver in a differential mode to meet EIA RS-422.

Am26LS29 AND Am26LS30 QUAD RS-423 LINE DRIVERS

The Am26LS29 and 30 consist of four single-ended line drivers designed to meet or exceed the requirements of RS-423. The buffered driver outputs are provided with sufficient source and sink current capability to drive 50 ohm to a virtual ground transmission line and high capacitive loads. The Am26LS29 has a three-state output control while the Am26LS30 has a Mode Control input that allows it to operate as a dual RS-422 driver (with suitable power supply changes), Figure 3.

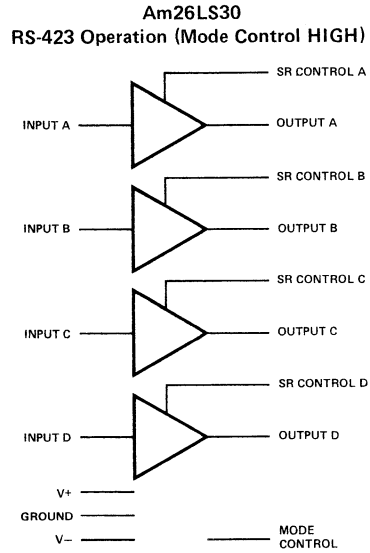
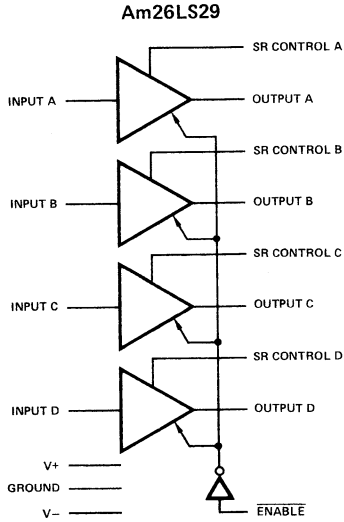
Each of the four driver inputs, as well as the Enable/Mode Control input is a PNP Low-Power Schottky input for reduced

input loading, one-half the normal fan-in. Since there are two inverters from each input to output, the driver is non-inverting. When operating in the RS-423 mode, the Am26LS29 and 30 require both +5V and -5V nominal value power supplies. This allows the outputs to swing symmetrically about ground - producing a true bipolar output. The Mode Control (Pin 4) of the Am26LS30 should be HI or tied to

TABLE II
ADVANCED MICRO DEVICES'
EIA COMPATIBLE DEVICES

EIA Standard	Drivers	Receivers
RS-232C	Am1488 Quad Driver Am9616 Triple Driver with logic control Am2616 Quad Driver also specified for CCITT V.24 and MIL-188C	Am1489, 1489A Quad Receivers with response control pin Am9617 Triple Receiver with optional hysteresis Am2617 Quad Receiver specified over MIL range
RS-422	Am26LS31 Quad Differential with three-state control gating	Am26LS32 Quad Differential Driver single-ended Receiver
RS-423	Am26LS29 Quad Driver with three-state output Am26LS30 Quad Driver with slew rate control	Am26LS32 Quad single-ended/ Differential Receiver

a) Logic Diagrams



b) Circuit Diagram for Am26LS30

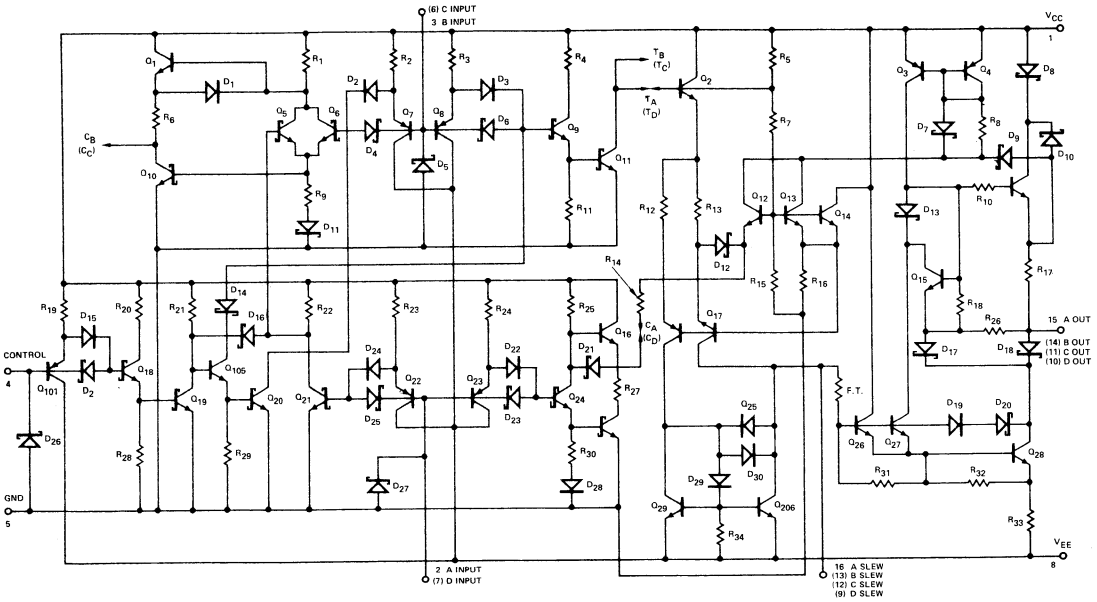


Figure 3. Am26LS29 and Am26LS30 Drivers.

V_{CC}. Each output is designed to drive the RS-423 load of 50 ohms with an output voltage equal or greater than +3.6 volts in the HI state and -3.6 volts in the LO state. Each output is current limited to 150mA max. in either logic state. A Slew Rate control pin is brought out separately for each output to allow output ramp rate (rise and fall time) control. This provides suppression of near end cross talk to other receivers in the cable. Connecting a capacitor from this node to that

driver's respective output will produce a ramp (10% to 90%) of 50ns typical for each picofarad of capacitance in that capacitor. RS-423 establishes recommended ramp rates versus length of line driven and modulation rate, Figure 4.

The Am26LS30 can be used at low data rates as a dual EIA RS-422 driver with three-state outputs by connecting the V_{EE} supply and the mode control input to ground.

Am26LS31 QUAD RS-422 DRIVER

The Am26LS31 is a quad differential line driver designed to meet the RS-422 specification while operating with a single +5 volt supply. A common enable and disable function controls all four drivers, Figure 5. The driver features high speed, de-skewed differential outputs with typical propagation delays of 12ns and residual skew of 2ns. Both differential line outputs are designed for three-state operation to allow two-way half duplex and multiplex, data bus applications.

Table III is a summary of the essential requirements of the RS-422 standard. Section A describes the key characteristics satisfied by the Am26LS31 driver.

The balanced differential line driver consists of two halves, each of which is similar to a Low-power Schottky TTL gate with equal source and sink current capability. The two halves are emitter coupled in a differential input configuration. One side of the input circuit is tied to a fixed TTL bias threshold and the other side is tied to a sink diode in normal DTL/TTL fashion. This configuration offers complementary outputs with very low skew, dependent only upon component matching, a necessity to meet RS-422.

The circuit diagram of the driver is shown in Figure 6. The emitter-coupled input circuit is formed by Q2 and Q3, which are biased by a current source. This source is a current mirror, formed by Q1 which supplies the current, and D6 which is diode connected transistor matched to Q1. The fixed bias for Q3, formed by D5 and D6, is $2V_{BE}$. A $2V_{BE}$ bias, less the D2 Schottky diode drop, provides the normal Low-power Schottky TTL threshold, $V_{IL} = 0.7V$. R19 provides a boost to 0.8V for a full 400mV TTL noise margin. The differential outputs of the emitter coupled stage, A and \bar{A} , drive emitter followers Q14 and Q15, which provide the required speed and matching characteristics. The emitter followers, drive phase splitters Q4 and Q5, which in turn drive totem-pole outputs. The outputs at the line interface are of standard Low-power Schottky TTL configuration, except that circuit values are modified to provide high sourcing capability. The outputs are designed to source or sink 20mA each, so that they can generate a voltage of at least 2.0V across a 100 ohm load, as required by RS-422. Additional circuitry has been included to make the line outputs three-state for two-way bus applications. The Am26LS31 meets the RS-422 requirement that the driver not load the line in the powered down condition ($I_X \leq 100\mu A$) or if the power supply to that device should fail.

Am26LS32 QUAD RS-422 AND 423 RECEIVER

The Am26LS32 is a quad line receiver which, operating from a single 5 volt supply, can be used in either differential or single-ended modes to satisfy RS-422 and 423 applications respectively. A complementary enable and disable feature, similar to that on the driver, controls all four receivers, Figure 7. The device's three-state outputs, which can sink 8mA, incorporate a fail-safe input-output relationship which keeps the outputs high when the inputs are open.

The Am26LS32 meets the receiver input specification of Table III, a 200mV threshold sensitivity with common mode rejection exceeding the supply line potentials, (greater than 7 volts). The same design feature of the input circuit which provides the common mode rejection also insures excellent power supply ripple rejection, which is important when switching the high currents involved in a system's interfaces. Furthermore, unlike operational amplifiers, where the DC common mode and power supply rejection ratios roll off with open loop gain, the full rejection capability of this line receiver is maintained at high frequencies. The receiver hysteresis of typically 30mV, provides differential noise immunity. Signals received on long lines can have slow transition times, and without hysteresis, a small amount of noise around the switching threshold can cause errors in the receiver output.

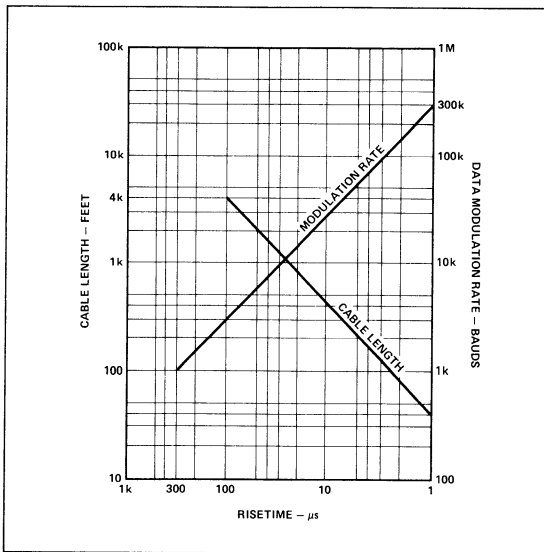


Figure 4. Data Modulation Rate or Cable Length Versus Risetime for EIA RS-423.

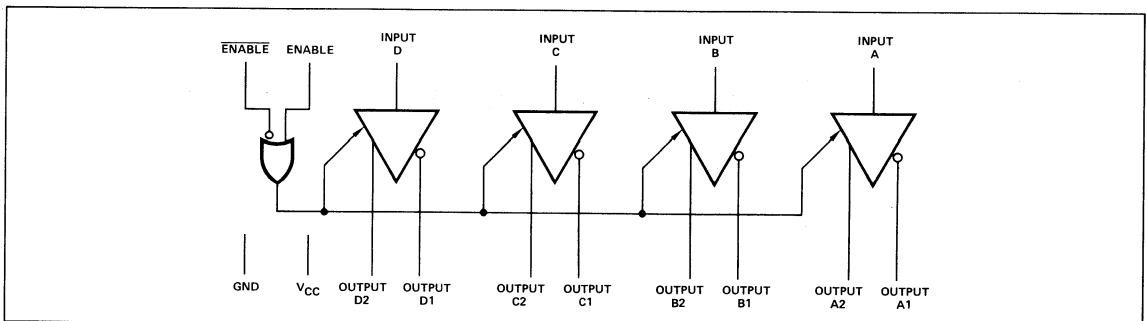


Figure 5. Am26LS31 Logic Diagram.

TABLE III
SUMMARY OF EIA RS-422 STANDARD FOR A BALANCED DIFFERENTIAL INTERFACE

<p>A. Line Driver</p> <p>Open Circuit Voltage (either logic state)</p> <p>Differential $V_{do} \leq 6.0V$</p> <p>Common Mode $V_{cmo} \leq 3.0V$</p> <p>Differential Output Voltage (across 100 ohm load)</p> <p>Either logic state $V_d \geq \max(0.5V_{dor}, 2.0V)$</p> <p>Output Impedance</p> <p>Either logic state $R_G \leq 100 \text{ ohms}$</p> <p>Mark-Space Level Symmetry (across 100 ohm load)</p> <p>Differential $V_{dS} - V_{dM} \leq 0.4V$</p> <p>Common Mode $V_{cmS} - V_{cmM} \leq 0.4V$</p> <p>Output Short Circuit Current (to ground)</p> <p>Either Output $I_{sc} \leq 150mA$</p> <p>Output Leakage Current (power off)</p> <p>Voltage Range $-0.25V \leq V_x \leq +6.0V$</p> <p>Either Output at V_x $I_x \leq 100\mu A$</p> <p>Rise and Fall Times (across 100 ohm load)</p> <p>T = Baud Interval $(t_r, t_f) \leq \max(0.1T, 20ns)$</p> <p>Ringing (across 100 ohm load)</p> <p>Definitions</p> <p>$V_{dSS} = V_d$ (steady state)</p> <p>$V_{SS} = V_{dS} - V_{dM}$ (steady state)</p> <p>Limits (either logic state)</p> <p>Percentage $V_d - V_{dSS} \leq 0.1V_{SS}$</p> <p>Absolute $2.0V \leq V_d \leq 6.0V$</p>	<p>B. Line Receiver</p> <p>Signal Voltage Range</p> <p>Differential $V_d \leq 6.0V$</p> <p>Common Mode $V_{cm} \leq 7.0V$</p> <p>Single-Ended Input Current (power ON or OFF)</p> <p>Either Input at V_x $V_x = 10V$</p> <p>Other Input Grounded $I_V \leq 3.25mA$</p> <p>Single-Ended Input Bias Voltage (other input grounded)</p> <p>Either Input Open Circuit $V_B \leq 3.0V$</p> <p>Single-Ended Input Impedance (other input grounded)</p> <p>Either Input $R_L \geq 4000 \text{ ohms}$</p> <p>Differential Threshold Sensitivity</p> <p>Common Mode Voltage Range $V_{cm} \leq 7.0V$</p> <p>Either Logic State $V_T \leq 200mV$</p> <p>Absolute Maximum Input Voltage</p> <p>Differential $V_d \leq 12V$</p> <p>Single-Ended $V_x \leq 10V$</p> <p>Input Balance (threshold shift)</p> <p>Common Mode Voltage Range $V_{cm} \leq 7.0V$</p> <p>Differential Threshold (500 ohms in series with each input)</p> <p>Either Logic State $V_T \leq 400mV$</p> <p>Termination (optional)</p> <p>Total Load Resistance (differential) $R_T > 90 \text{ ohms}$</p> <p>Multiple Receivers (bus applications)</p> <p>Up to 10 receivers allowed. Differential threshold sensitivity of 200mV must be maintained.</p> <p>Hysteresis (optional)</p> <p>As required for applications with slow rise/fall time at receiver, to control oscillations.</p> <p>Fail Safe (optional)</p> <p>As required by application to provide a steady MARK or SPACE condition under open connector or driver power</p> <p>OFF condition.</p>
<p>C. Interconnecting Cable</p> <p>Type</p> <p>Twisted Pair Wire or Flat Cable Conductor Pair</p> <p>Conductor Size</p> <p>Copper Wire (solid or stranded) 24 AWG or larger</p> <p>Other (per conductor) $R \leq 30 \text{ ohms/1000 ft.}$</p> <p>Capacitance</p> <p>Mutual Pair $C \leq 20pF/ft.$</p> <p>Stray $C \leq 40pF/ft.$</p> <p>Pair-to-Pair Cross Talk (balanced)</p> <p>Attenuation at 150KHz $A \geq 40dB$</p>	

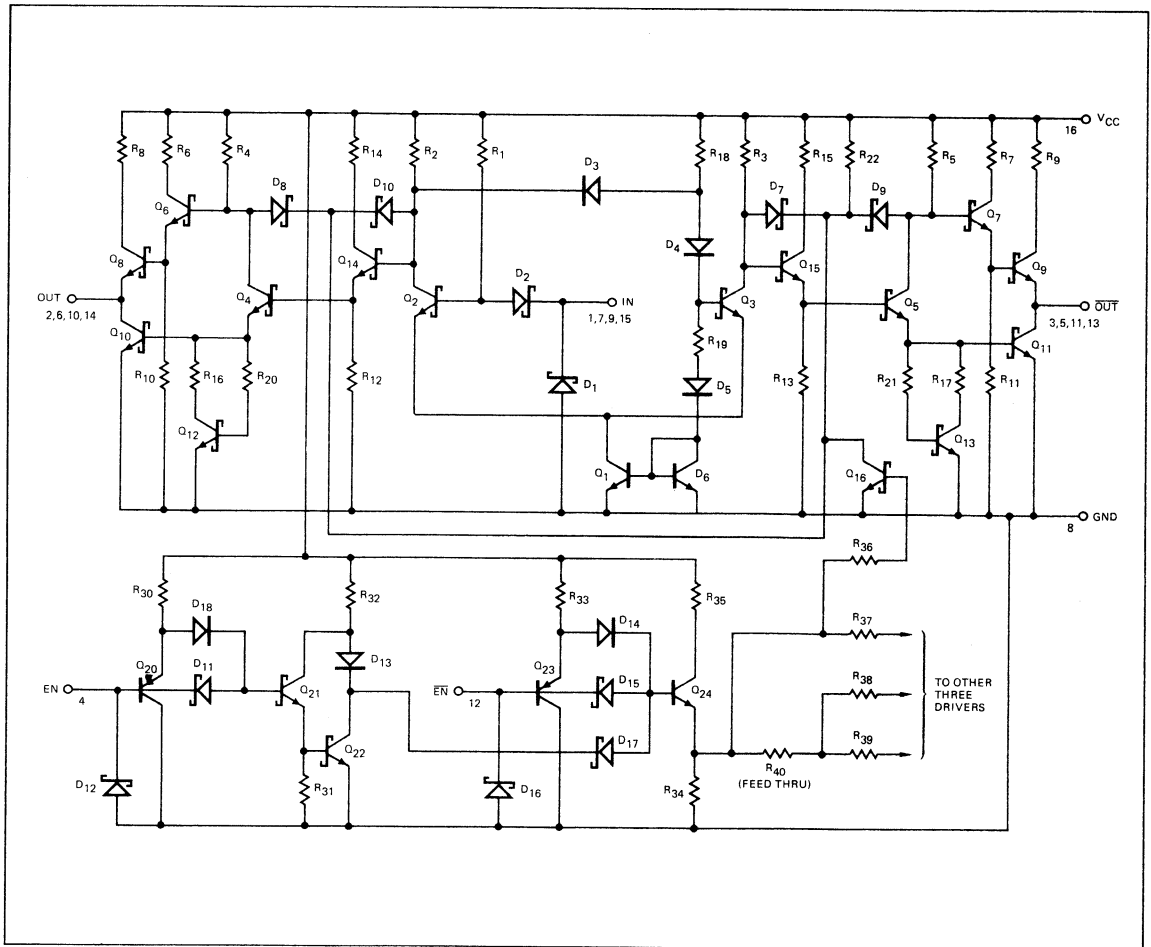


Figure 6. Am26LS31 Circuit Diagram (Only one driver shown).

The balanced differential line receiver is a three-stage circuit. The input stage consists of a low-impedance differential current amplifier with series resistor inputs to convert line signal voltage to current and provide a moderate input impedance. The input resistors provide an impedance greater than 6K on each input, power on or power off, which exceeds the requirements of RS-422 and RS-423. This is one advantage of the current amplifier input circuit. Another advantage is that it can operate with immunity to common mode voltages above V_{CC} and below ground. The differential threshold sensitivity of this circuit is 200mV, as required by RS-422. The second stage is a differential voltage amplifier, which interfaces to the single-ended output stage through an emitter follower. The output stage is a standard Low-power Schottky TTL totem-pole output with three-state capability.

The full circuit is shown in Figure 8. Resistors R_{20} and R_{21} , which connect the non-inverting input to V_{CC} and the inverting input to ground, provide the fail-safe feature, which guarantees a HIGH logic state for the receiver output when there is no signal on the line. The differential voltage amplifier in the second stage is formed by Q_6 and Q_3 which are biased by current source Q_9 . The hysteresis in the re-

ceiver switching characteristic is provided by Q_4 and Q_5 , a differential pair biased by current source Q_6 , whose collectors are connected in positive feedback to the input pull-up circuits. A small amount of current is switched by Q_4 and Q_5 , which must be overcome by the different voltage signal, resulting in the hysteresis. The output stage is driven from one side of the differential second stage by emitter follower Q_{17} , which is a multiple emitter transistor. The second emitter is the control point for the three-state output. Q_{17} drives the phase splitter Q_{12} , which in turn drives the three-state totem-pole output. The remainder of the circuit is the output enable control logic. This three-state capability on the receiver TTL side of the interface is a useful feature for modularizing two-way bus design.

A mask option of the input resistors (R_1 , R_2 , R_{20} and R_{21}) modifies the receiver characteristics to improve operation in high common mode noise environments. This device, known as the Am26LS33, has these resistors at twice the value of the Am26LS32. An input differential or common mode voltage range of ± 15 volts is achieved at the expense of a minor decrease of input threshold sensitivity, to ± 500 mV from ± 200 mV.

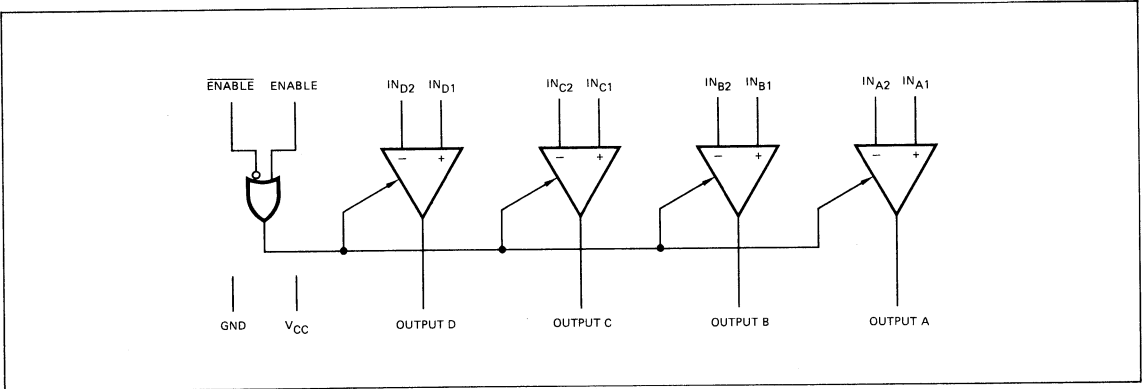


Figure 7. Am26LS32 Logic Diagram.

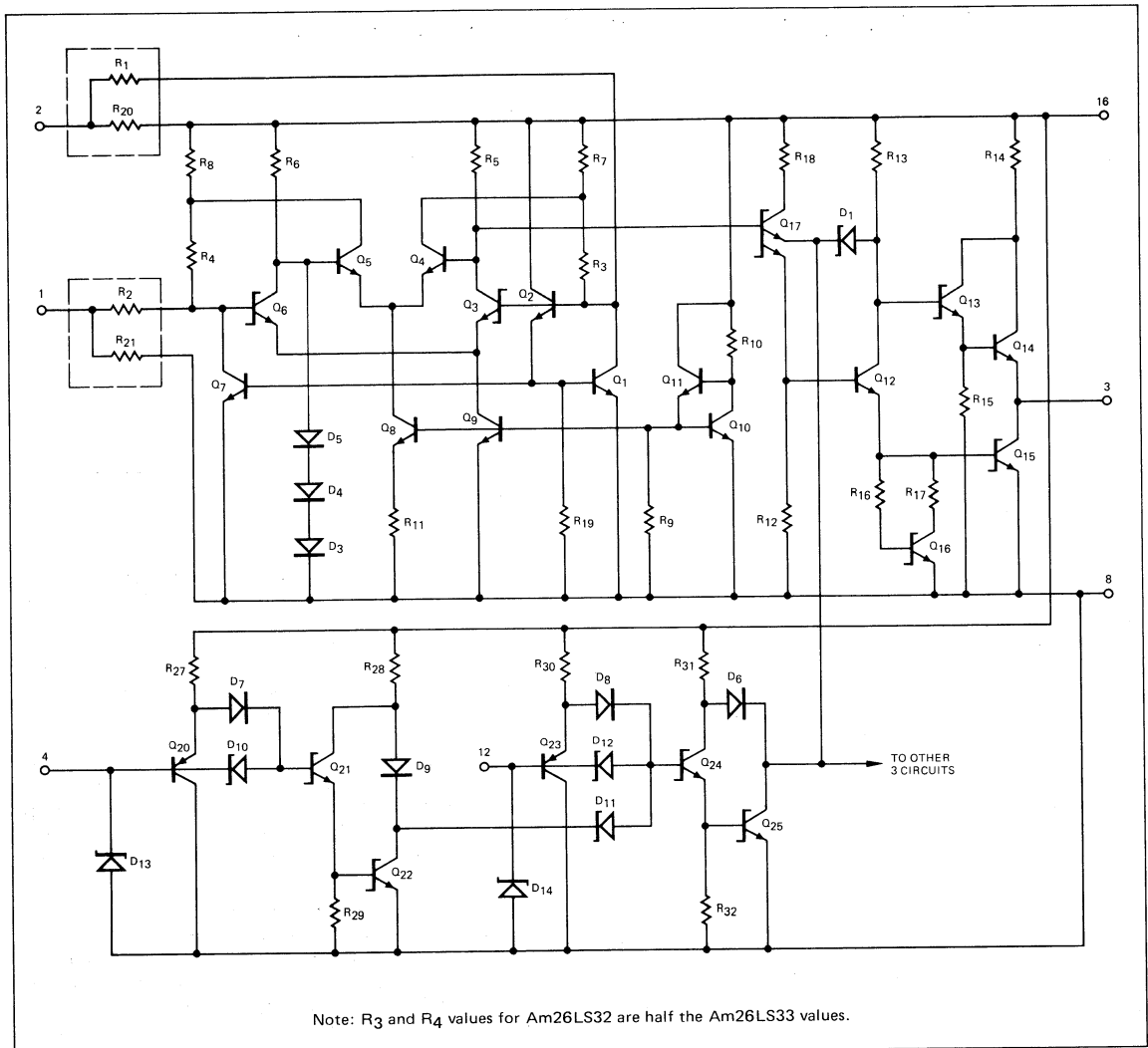


Figure 8. Am26LS32 and Am26LS33 Circuit Diagram (Only one receiver shown).

APPLICATIONS IN MIXED RS-232 AND 422/3 SYSTEMS

A system implemented with the RS-422 differential output cannot be used to drive an RS-232C system directly. An RS-423 single-ended driver, such as the Am26LS29 or Am26LS30, may be used provided certain precautions are observed.

1. Although the RS-423 driver output specification of between 4 to 5V does not meet the RS-232C specification of 6V, operation is usually satisfactory with RS-232C receivers. This is achieved because the short cable lengths permitted by RS-232C cause very little signal degradation and because of the low source impedance of the RS-423 driver.
2. RS-232C specifies that the rise time for the signal to pass through the $\pm 3.0V$ transition region shall not exceed 4% of the signal element duration. RS-423 requires much slower rise times, specified from 10% to 90% of the total signal amplitude, to reduce cross talk for operation over longer distances. Therefore, the RS-423 driver in the equipment must be waveshaped. This is achieved by selection of a capacitor value for the Am26LS30 to simultaneously meet the requirements of both RS-423 and RS-232C for data rates covered by RS-232C.
3. RS-423 specifies one common return ground for each direction of transmission, RS-232C requires only one for both directions of transmission. Care must be taken to insure that a return ground path has been created when interfacing between the two systems.
4. RS-232C does not require termination, while it may be necessary for RS-422 and 423. Detailed consideration of termination is covered in the next section.

Note that RS-422 and RS-423 specifies that receivers should not be damaged by voltages up to 12V, while RS-232C allows drivers to produce output voltages up to 25V. The Am26LS32 receiver has been designed to avoid this hazard and can withstand input voltages of ± 25 volts.

RS-422 TRANSMISSION LINE FEATURES

Any time a receiver and transmitter are connected with more than a few inches of a wire, problems due to reflections can arise if care is not exercised to terminate the line correctly. RS-422 describes the cable as a twisted pair of approximately 120Ω impedance terminated in a resistor R_T . R_T is not specified because there are two extreme values which may be chosen for the two following general classes of usage: (1) single direction transmission; and (2) multi-direction and multiple source transmission (party line). Considering the cable impedance only, the termination should equal the cable impedance of 120Ω . However this reduces the terminated cable resistance as seen by the driver to only 60Ω , with resulting loading of the output signal. This loading causes a reduction of S/N ratio at the received terminal due to the decrease in signal voltage swing. The solution lies in a compromise between an R_T of 120Ω which provides maximum power transfer at a reduced S/N ratio or R_T of 240Ω which causes a mis-match of 2-to-1 but no S/N reduction. The choice is left to the user as it is system dependent. Both schemes will work for an average line length and should only approach the margins at maximum line length and maximum bit rates.

Electronic Industries Association, when preparing EIA Stan-

ard RS-422 conducted their tests with 24 gauge twisted pair wire. The resulting length vs. data rate, is published as a guideline in RS-422 (Figure 9). This shows two important results: (1) Unmodulated baseband (NRZ) signalling is not recommended at distances greater than 4000 feet; (2) At data

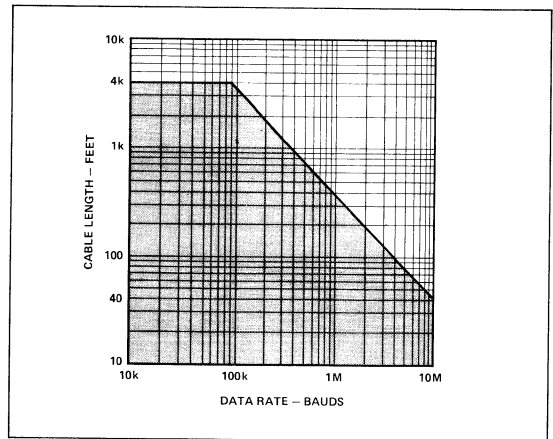


Figure 9. Data Rate Versus Cable Length for Balanced, Twisted Pair Cable (From EIA RS-422).

rates above about 100KHz, the maximum cable length for acceptable signal quality is inversely proportional to data rate.

Result (1) above is due to the DC resistance of the cable. For a 4000 foot cable with a DC resistance of 30 ohms/1000 feet, the DC series loop resistance is 240Ω . The minimum allowable terminated differential load impedance is 90Ω . The DC voltage attenuation is $90/(90 - 240) = 1/4(6db)$, which is arbitrarily chosen as the maximum allowable limit.

Result (2) is due to line losses. Laboratory tests using the 26LS31 Line Driver connected to the 26LS32 Line Receiver by 800 feet of ordinary 20 AWG twisted pair (Beldon #8205 plastic-jacketed wire), terminated in its characteristic impedance of 100Ω were evaluated. The input waveform was a 500KHz square wave with (10% to 90%) rise and fall times of less than 10ns. The output waveform produced rise and fall times which together accounted for approximately one-half the period ($t_r + t_f = 500ns$). This was due to line loss and constant capacity. The energy per cycle of the output waveform is approximately 25% lower than that of the input. The input rise and fall times are not a function of line length, assuming matching termination. The output rise and fall times are dependent upon length in a complex manner. Furthermore, it can be shown by observation that they build up along the line.

Many good reference sources are available on the subject of transmission lines (References 1, 2, 3 and 4). These will provide background information to the following discussion.

Seshadri in Reference (1) has analyzed a line with series resistance losses and has shown that rise time varies with the square of the length. This shows series resistance to be a function of the square root of frequency. However when one tries to use this result in combination with the previous result, it becomes apparent just how difficult the problem is. In Reference (2), the authors point out that skin depth implies a frequency dependent series inductance as well as resistance, and that one cannot be considered without the other.

They go on to show how this leads to the same result; namely that rise and fall times vary with the square of distance.

No attempt will be made to explain here why Figure 5 shows maximum length varying inversely with frequency rather than with the square of frequency. Certainly many complex factors are involved. Our laboratory observations showed a dependence somewhere in between linear and square law.

The Am26LS31 Quad Line Driver and the Am26LS32 Quad Line Receiver are capable of good, clean operation to the distance limits and data rate limits of RS-422.

SYSTEM APPLICATIONS

The Am26LS30, 31, 32 and 33 can be combined in various

signaling networks. Using Am26LS29, Am26LS30 and Am26LS32, Figure 10, a unidirectional RS-423 communication can be constructed. Allowing for the voltage variation described earlier, RS-232C requirements can be satisfied. It should be noted that the Am26LS29 or Am26LS30 is used above to meet the bipolar requirements. If a single-ended line, Figure 11, is required without a bipolar requirement, the Am26LS31 can be used by biasing the reference terminal of the receiver to approximately 1.5 volts. Note that additional resistors will enhance fail safe operation.

Figure 12 shows the use of the Am26LS31 and Am26LS32 to meet a balanced line, single direction RS-422 application. If bidirectionality is required, an additional termination should be added as shown in Figure 13.

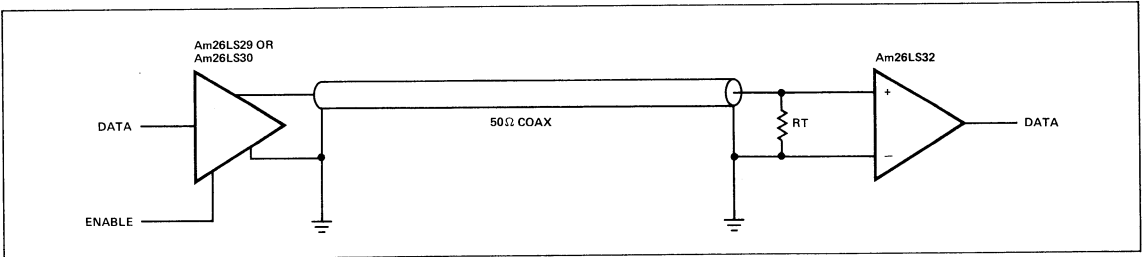


Figure 10. Unidirectional RS-423 (partial RS-232C).

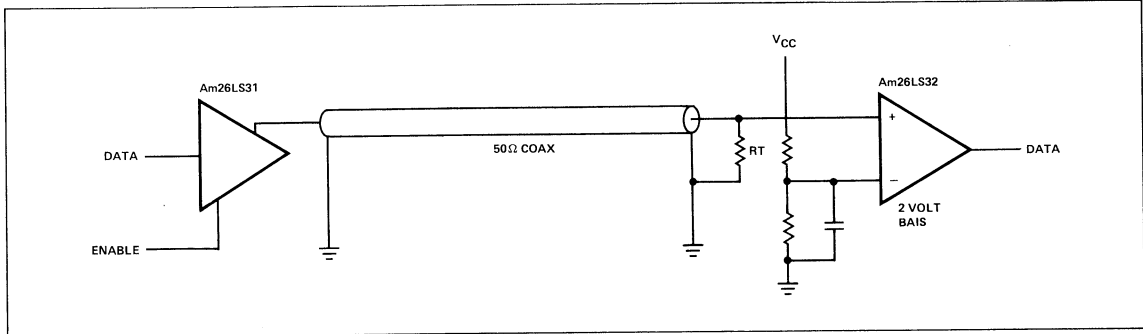


Figure 11. Single-Ended Line Without Bipolar Requirement.

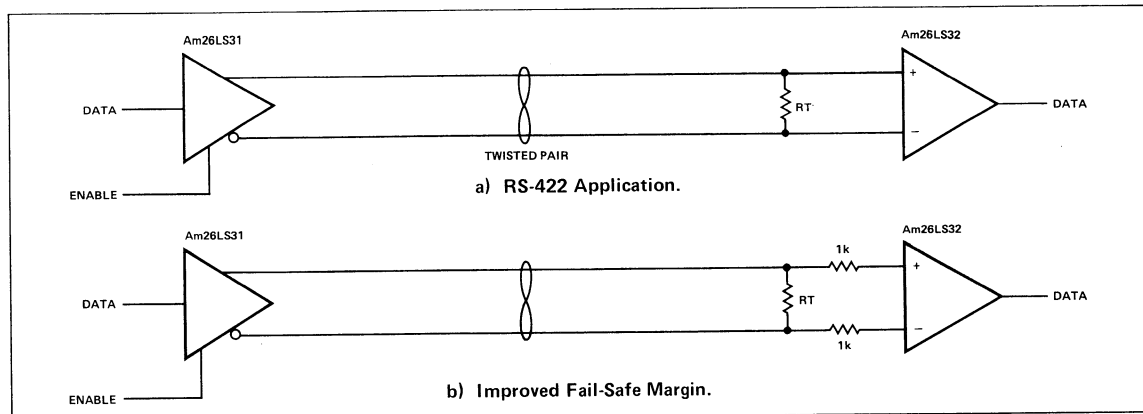


Figure 12.

3

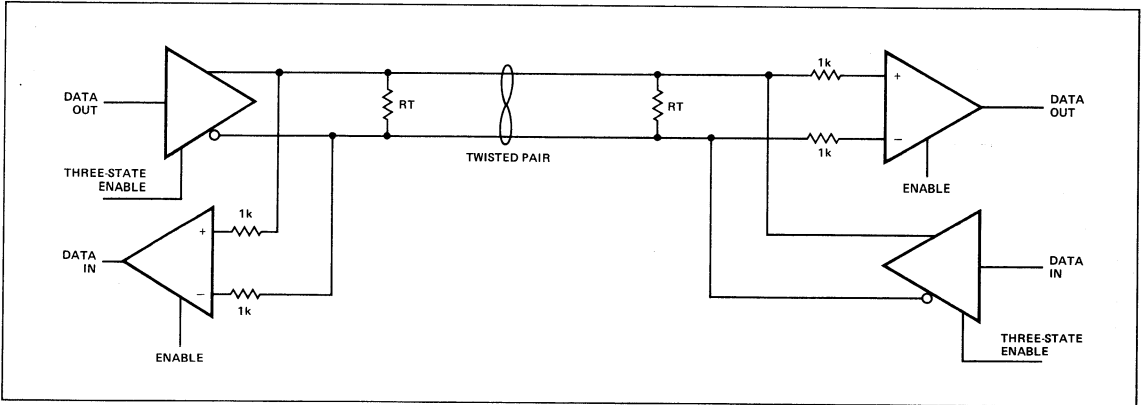


Figure 13. Bidirectional RS-422.

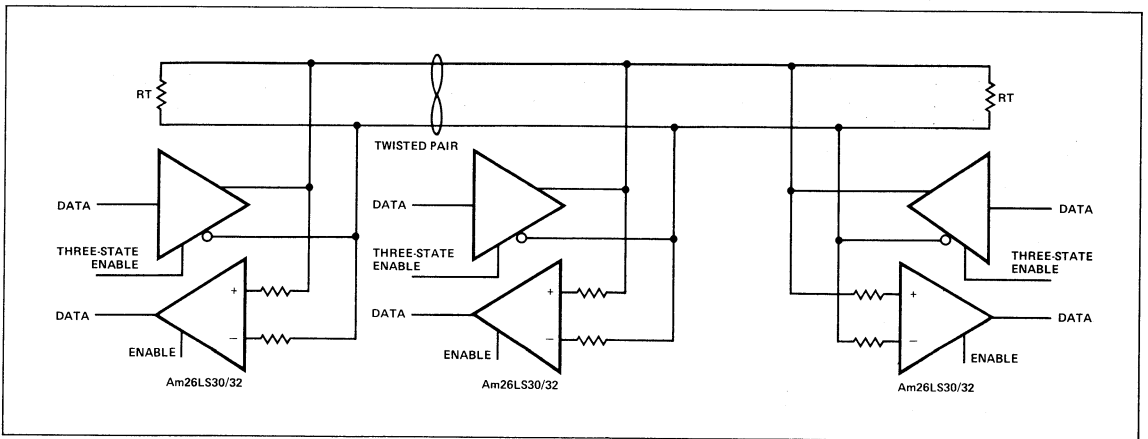


Figure 14. Party Line Configuration.

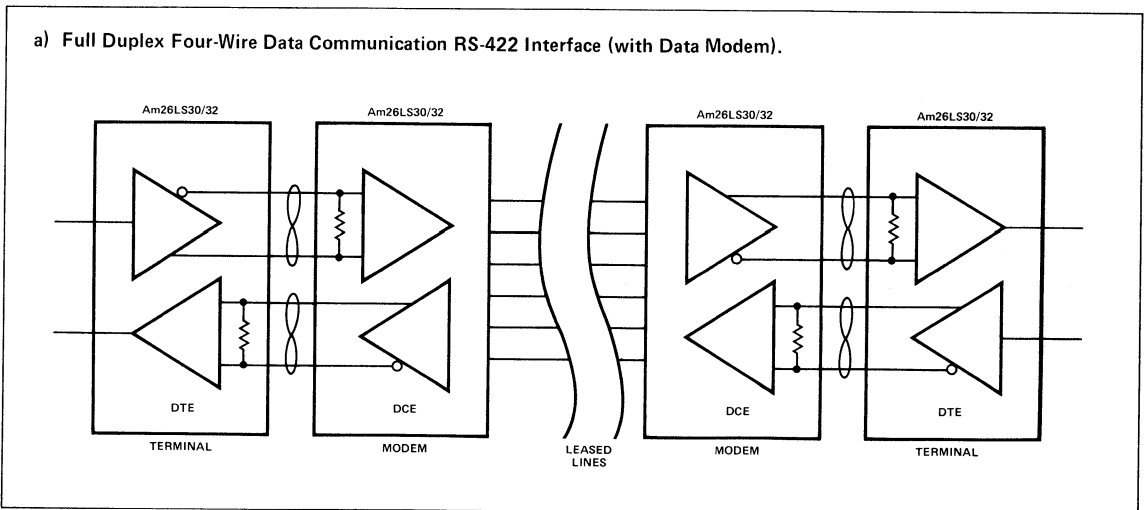


Figure 15.

b) Full Duplex Four-Wire Data Communication
RS-422 Interface (without Data Modem).

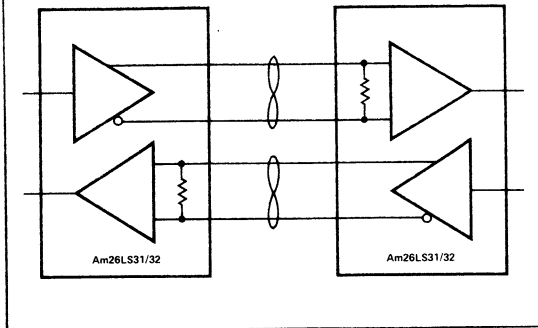


Figure 15. (Cont.)

The high speed capability of RS-422 has attracted the interest of many computer designers for use in the party line mode (Figure 14). The most common usage is that of a four wire full duplex exchange system (Figure 15). This mode of operation involves two pairs of wires each handling a single direction of traffic. The outgoing direction consists of one driver (Am26LS30 or Am26LS31) and n receivers (Am26LS32 or Am26LS33). The incoming direction consists of one receiver (Am26LS32 or Am26LS33) and n drivers (Am26LS30 or Am26LS31). This seems extremely simple to organize. However, problems arise when system ground is considered. If the network of receiver and driver span a moderate to long physical distance, ground loop noise or differences are developed changing the voltage that appears at the terminals of all receivers and drivers except for the one driver that is ac-

tive. It remains the system reference as long as it is active. This induced or system developed voltage is referred to as Common Mode voltage (CMV) and as such must be considered as a device parameter. All manufacturers specify CMV capability of their receiver in compliance with RS-422 (approx. 7 volts plus signal) but there is no specification for drivers. If the dimensions of the system are short compared to $1/4$ wave length of the maximum data rise and fall times, the CMV can be assumed to be minimal and drivers with single voltage supply and limited negative CMV can be used, i.e., Am26LS31. If the system dimensions are large, the CMV will cause problems in that the driver will clamp to the ground the moment the collective or apparent voltage swings below minus 0.5 volts relative to the driver ground, causing a short in the line and increasing level shift and noise. The clamping is caused in part by conduction of the I/C substrate diode. The problem can be avoided by using a driver with an output common mode range (Am26LS30). The Am26LS30 guarantees an output CMV range of ± 10 volts about the driver ground reference. New international standards are under consideration to specify this mode of operation. In conclusion, a good system of 4 wire full duplex for data communication would use as an outgoing pair an Am26LS30 line driver and up to 12 - Am26LS32 line receivers, with a termination at the near and far ends of the cable. The same system would use as an incoming pair an Am26LS32 line receiver and up to 32 - Am26LS30 line drivers with only one enabled at a time and all others in three-state mode with cable termination at both near and far ends of the cable.

Many other applications are possible using this family of devices. Although the designs are based on the requirements of the EIA data communications specifications, they are not limited to these situations. Aircraft buses and internal equipment interconnections will benefit from the features offered by these products.

REFERENCES

1. Seshadri, S. R., *Fundamental of Transmission Lines and Electromagnetic Fields*, (U. of Wisconsin), Addison-Wesley, Reading, Mass., 1971.
2. Adler, R. B., L. J. Chu, and R. M. Fano, *Electromagnetic Energy Transmission and Radiation*, (MIT), John Wiley & Sons, New York, 1963.
3. Matick, R. E., *Transmission Lines for Digital and Communication Networks*, (IBM), McGraw-Hill, New York, 1969.
4. *Reference Data for Radio Engineers*, (ITT), Fifth Edition, Howard W. Sams & Company, Indianapolis, 1974.
5. Electronic Industries Association, 2001 Eye Street, N.W. Washington, D.C., RS Standard Proposal, RS-232C, August, 1969.
6. Electronic Industries Association, 2001 Eye Street, N.W. Washington, D.C., RS Standard Proposal 1220, Rev. RS-422, September 21, 1976.
7. Electronic Industries Association, 2001 Eye Street, N.W. Washington, D.C., RS Standard Proposal 1221, Rev. RS-423, September 21, 1976.

Am2905

Quad Two-Input OC Bus Transceiver With Three-State Receiver

Distinctive Characteristics

- Quad high-speed LSI bus-transceiver
- Open-collector bus driver
- Two-port input to D-type register on driver
- Bus driver output can sink 100 mA at 0.8V max.
- Receiver has output latch for pipeline operation
- Three-state receiver outputs sink 12 mA
- Advanced low-power Schottky processing
- 100% reliability assurance testing in compliance with MIL-STD-883

FUNCTIONAL DESCRIPTION

The Am2905 is a high-performance, low-power Schottky bus transceiver intended for bipolar or MOS microprocessor system applications. The device consists of four D-type edge-triggered flip-flops with a built-in two-input multiplexer on each. The flip-flop outputs are connected to four open-collector bus drivers. Each bus driver is internally connected to one input of a differential amplifier in the receiver. The four receiver differential amplifier outputs drive four D-type latches that feature three-state outputs.

This LSI bus transceiver is fabricated using advanced low-power Schottky processing. All inputs (except the BUS inputs) are one LS unit load. The open-collector bus output can sink up to 100 mA at 0.8V maximum. The BUS input differential amplifier contains disconnect protection diodes such that the bus is fail-safe when power is not applied. The bus enable input (\overline{BE}) is used to force the driver outputs to the high-impedance state. When \overline{BE} is HIGH, the driver is disabled. The open-collector structure of the driver allows wired-OR operations to be performed on the bus.

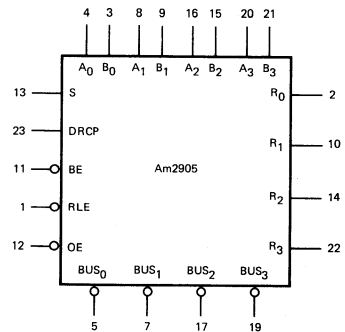
The input register consists of four D-type flip-flops with a buffered common clock and a two-input multiplexer at the input of each flip-flop. A common select input (S) controls the four multiplexers. When S is LOW, the A_i data is stored in the register and when S is HIGH, the B_i data is stored. The buffered common clock (DRCP) enters the data into this driver register on the LOW-to-HIGH transition.

Data from the A or B inputs is inverted at the BUS output. Likewise, data at the BUS input is inverted at the receiver output. Thus, data is non-inverted from driver input to receiver output. The four receivers each feature a built-in D-type latch that is controlled from the buffered receiver latch enable (\overline{RLE}) input. When the \overline{RLE} input is LOW, the latch is open and the receiver outputs will follow the bus inputs (BUS data inverted and \overline{OE} LOW). When the \overline{RLE} input is HIGH, the latch will close and retain the present data regardless of the bus input. The four latches have three-state outputs and are controlled by a buffered common three-state control (\overline{OE}) input. When \overline{OE} is HIGH, the receiver outputs are in the high-impedance state.

ORDERING INFORMATION

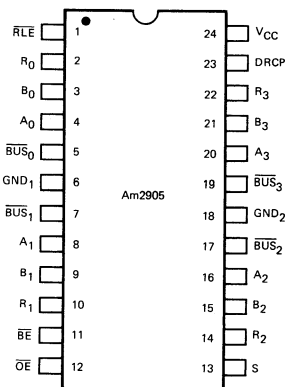
Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM2905PC
Hermetic DIP	0°C to +70°C	AM2905DC
Dice	0°C to +70°C	AM2905XC
Hermetic DIP	-55°C to +125°C	AM2905DM
Hermetic Flat Pak	-55°C to +125°C	AM2905FM
Dice	-55°C to +125°C	AM2905XM

LOGIC SYMBOL



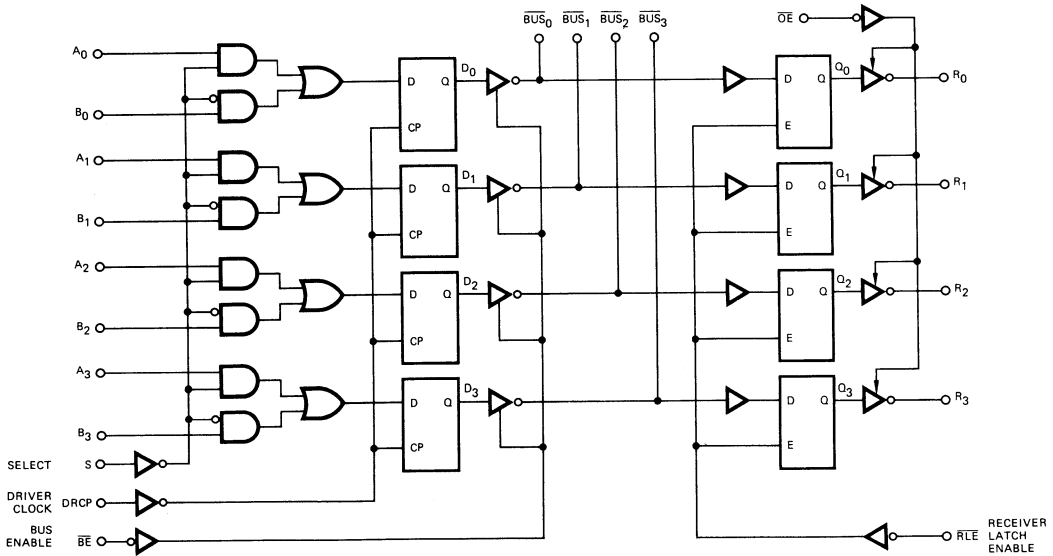
V_{CC} = Pin 24
 GND_1 = Pin 6
 GND_2 = Pin 18

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC DIAGRAM



MPR-065

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7V
DC Output Current, Into Outputs (Except Bus)	30mA
DC Output Current, Into Bus	200mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2905XC (COM'L)	T _A = 0°C to +70°C	V _{CC} MIN. = 4.75 V	V _{CC} MAX. = 5.25 V
Am2905XM (MIL)	T _A = -55°C to +125°C	V _{CC} MIN. = 4.50 V	V _{CC} MAX. = 5.50 V

BUS INPUT/OUTPUT CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V _{OL}	Bus Output LOW Voltage	V _{CC} = MIN.	I _{OL} = 40mA		0.32	0.5	Volts
			I _{OL} = 70mA		0.41	0.7	
			I _{OL} = 100mA		0.55	0.8	
I _O	Bus Leakage Current	V _{CC} = MAX.	V _O = 4.5V	MIL		200	μA
				COM'L		100	
I _{OFF}	Bus Leakage Current (Power OFF)	V _O = 4.5V				100	μA
V _{TH}	Receiver Input HIGH Threshold	Bus enable = 2.4V	MIL	2.4	2.0		Volts
			COM'L	2.3	2.0		
V _{TL}	Receiver Input LOW Threshold	Bus enable = 2.4V	MIL		2.0	1.5	Volts
			COM'L		2.0	1.6	

Am2905

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2905XC (COM'L) $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC\text{MIN.}} = 4.75\text{V}$ $V_{CC\text{MAX.}} = 5.25\text{V}$

Am2905XM MIL $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC\text{MIN.}} = 4.50\text{V}$ $V_{CC\text{MAX.}} = 5.50\text{V}$

DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

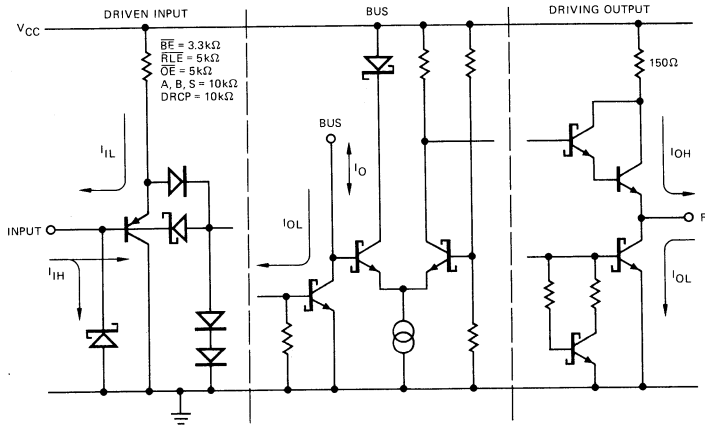
Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)			Units
			Min.	Max.	Max.	
VOH	Receiver Output HIGH Voltage	$V_{CC} = V_{IN}$ $V_{IN} = V_{IL}$ or V_{IH}	MIL, $I_{OH} = -1.0\text{mA}$	2.4	3.4	Volts
			COM'L, $I_{OH} = -2.6\text{mA}$	2.4	3.4	
VOL	Receiver Output LOW Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IL}$ or V_{IH}	$I_{OL} = 4\text{mA}$		0.27	Volts
			$I_{OL} = 8\text{mA}$		0.32	
			$I_{OL} = 12\text{mA}$		0.37	
VIH	Input HIGH Level (Except Bus)	Guaranteed input logical HIGH for all inputs	2.0		Volts	
VIL	Input LOW Level (Except Bus)	Guaranteed input logical LOW for all inputs	MIL		0.7	Volts
			COM'L		0.8	
VI	Input Clamp Voltage (Except Bus)	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$			-1.5	Volts
IIL	Input LOW Current (Except Bus)	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$			-0.36	mA
IiH	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$			20	μA
Ii	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}$, $V_{IN} = 5.5\text{V}$			100	μA
IO	Receiver Off-State Output Current	$V_{CC} = \text{MAX.}$	$V_O = 2.4\text{V}$		20	μA
			$V_O = 0.4\text{V}$		-20	
ISC	Receiver Output Short Circuit Current	$V_{CC} = \text{MAX.}$	-12		-65	mA
ICC	Power Supply Current	$V_{CC} = \text{MAX.}$, All inputs = GND		69	105	mA

SWITCHING CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions	Am2905XM			Am2905XC			Units
			Min.	Typ. (Note 2)	Max.	Min.	Typ. (Note 2)	Max.	
tPHL	Driver Clock (DRCP) to Bus	C_L (BUS) = 50 pF R_L (BUS) = 50 Ω		21	40		21	36	ns
tPLH				21	40		21	36	
tPHL	Bus Enable (\overline{BE}) to Bus			13	26		13	23	ns
tPLH				13	26		13	23	
ts	Data Inputs (A or B)						23		ns
th							7.0		
ts	Select Input (S)						30		ns
th							7.0		
tpW	Driver Clock (DRCP) Pulse Width (HIGH)		28				25		ns
tPLH	Bus to Receiver Output (Latch Enable)	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$		18	37		18	34	ns
tPHL				18	37		18	34	
tPLH	Latch Enable to Receiver Output			21	37		21	34	ns
tPHL				21	37		21	34	
ts	Bus to Latch Enable (\overline{RLE})						18		ns
th							5.0		
tZH	Output Control to Receiver Output			14	28		14	25	ns
tZL				14	28		14	25	
tHZ	Output Control to Receiver Output			14	28		14	25	ns
tLZ				14	28		14	25	

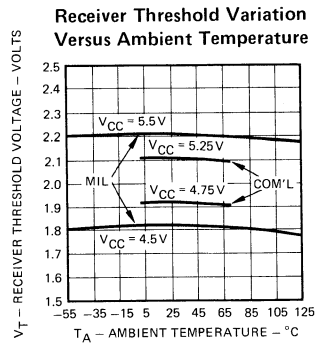
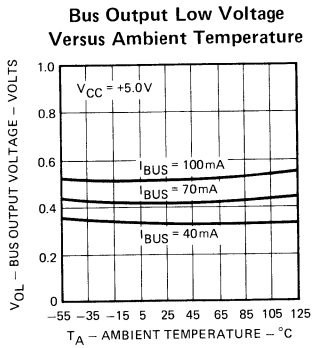
- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



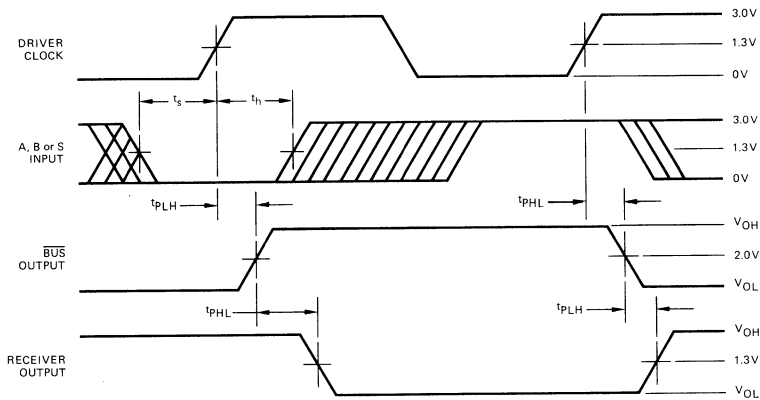
Note: Actual current flow direction shown.

TYPICAL PERFORMANCE CURVES



3

SWITCHING WAVEFORMS



Note: Bus to Receiver output delay is measured by clocking data into the driver register and measuring the BUS to R combinatorial delay.

FUNCTION TABLE

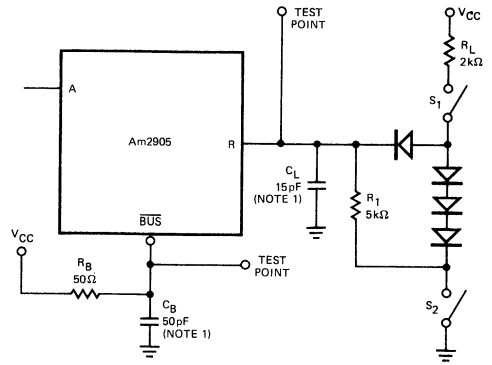
INPUTS							INTERNAL TO DEVICE		BUS	OUTPUT	FUNCTION
S	A _i	B _i	DRCP	\overline{BE}	\overline{RLE}	\overline{OE}	D _i	Q _i	\overline{BUS}_i	R _i	
X	X	X	X	H	X	X	X	X	Z	X	Driver output disable
X	X	X	X	X	X	H	X	X	X	Z	Receiver output disable
X	X	X	X	H	L	L	X	L	L	H	Driver output disable and receive data via Bus input
X	X	X	X	H	L	L	X	H	H	L	
X	X	X	X	X	H	X	X	NC	X	X	Latch received data
L	L	X	↑	X	X	X	L	X	X	X	Load driver register
L	H	X	↑	X	X	X	H	X	X	X	
H	X	L	↑	X	X	X	L	X	X	X	
H	X	H	↑	X	X	X	H	X	X	X	
X	X	X	L	X	X	X	NC	X	X	X	No driver clock restrictions
X	X	X	H	X	X	X	NC	X	X	X	
X	X	X	X	L	X	X	L	X	H	X	Drive Bus
X	X	X	X	L	X	X	H	X	L	X	

H = HIGH Z = HIGH Impedance X = Don't care i = 0, 1, 2, 3
 L = LOW NC = No change ↑ = LOW-to-HIGH transition

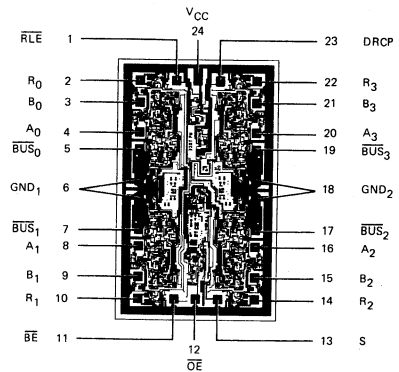
DEFINITION OF FUNCTIONAL TERMS

- A₀, A₁, A₂, A₃** The "A" word data input into the two input multiplexer of the driver register.
- B₀, B₁, B₂, B₃** The "B" word data input into the two input multiplexers of the driver register.
- S** Select. When the select input is LOW, the A data word is applied to the driver register. When the select input is HIGH, the B word is applied to the driver register.
- DRCP** Driver Clock Pulse. Clock pulse for the driver register.
- \overline{BE}** Bus Enable. When the Bus Enable is HIGH, the four drivers are in the high impedance state.
- $\overline{BUS}_0, \overline{BUS}_1, \overline{BUS}_2, \overline{BUS}_3$** The four driver outputs and receiver inputs (data is inverted).
- R₀, R₁, R₂, R₃** The four receiver outputs. Data from the bus is inverted while data from the A or B inputs is non-inverted.
- \overline{RLE}** Receiver Latch Enable. When RLE is LOW, data on the BUS inputs is passed through the receiver latches. When RLE is HIGH, the receiver latches are closed and will retain the data independent of all other inputs.
- \overline{OE}** Output Enable. When the \overline{OE} input is HIGH, the four three state receiver outputs are in the high-impedance state.

LOAD TEST CIRCUIT

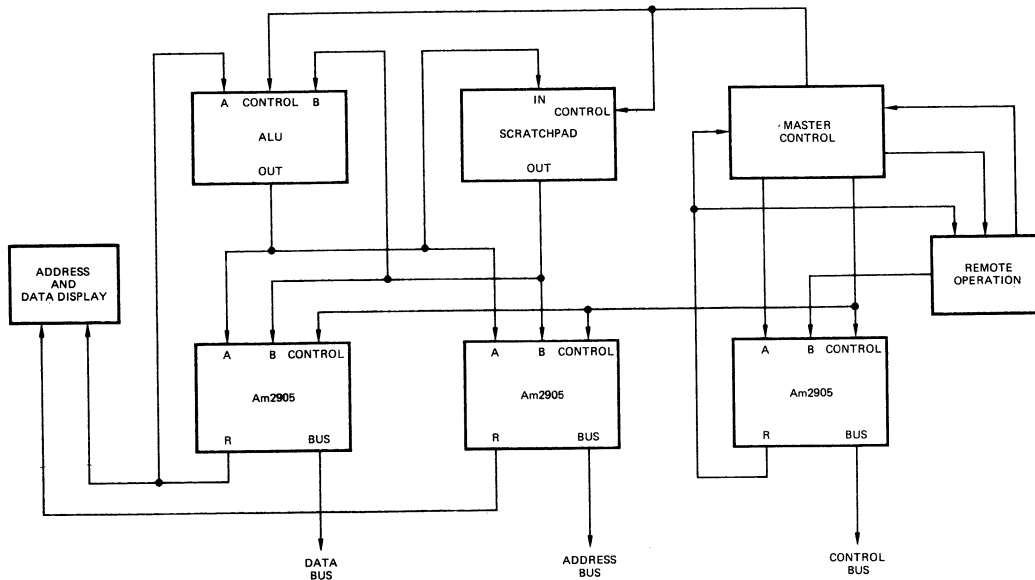


Metallization and Pad Layout



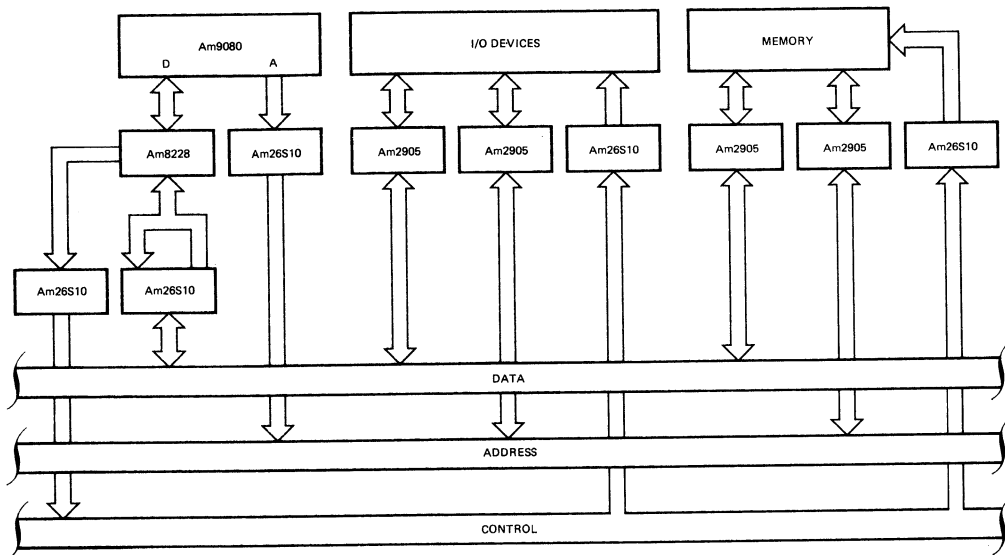
DIE SIZE 0.080" X 0.130"

APPLICATIONS



The Am2905 is a universal Bus Transceiver useful for many system data, address, control and timing input/output interfaces.

3



Using the Am2905 and Am26S10 in a terminated Bus system for the Am9080 MOS Microprocessor.

Am2906

Quad Two-Input OC Bus Transceiver With Parity

Distinctive Characteristics

- Quad high-speed LSI bus transceiver.
- Open-collector bus driver.
- Two-port input to D-type register on driver.
- Bus driver output can sink 100 mA at 0.8V max.
- Internal odd 4-bit parity checker/generator.
- Receiver has output latch for pipeline operation.
- Receiver outputs sink 12 mA.
- Advanced low-power Schottky processing.
- 100% reliability assurance testing in compliance with MIL-STD-883.

FUNCTIONAL DESCRIPTION

The Am2906 is a high-performance, low-power Schottky bus transceiver intended for bipolar or MOS microprocessor system applications. The device consists of four D-type edge-triggered flip-flops with a built-in two-input multiplexer on each. The flip-flop outputs are connected to four open-collector bus drivers. Each bus driver is internally connected to one input of a differential amplifier in the receiver. The four receiver differential amplifier outputs drive four D-type latches. The device also contains a four-bit odd parity checker/generator.

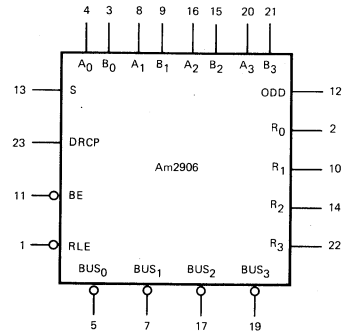
This LSI bus transceiver is fabricated using advanced low-power Schottky processing. All inputs (except the BUS inputs) are one LS unit load. The open-collector bus output can sink up to 100 mA at 0.8V maximum. The BUS input differential amplifier contains disconnect protection diodes such that the bus is fail-safe when power is not applied. The bus enable input (\overline{BE}) is used to force the driver outputs to the high-impedance state. When \overline{BE} is HIGH, the driver is disabled. The open-collector structure of the driver allows wired-OR operations to be performed on the bus.

The input register consists of four D-type flip-flops with a buffered common clock and a two-input multiplexer at the input of each flip-flop. A common select input (S) controls the four multiplexers. When S is LOW, the A_i data is stored in the register and when S is HIGH, the B_i data is stored. The buffered common clock (DRCP) enters the data into this driver register on the LOW-to-HIGH transition.

Data from the A or B input is inverted at the BUS output. Likewise, data at the BUS input is inverted at the receiver output. Thus, data is non-inverted from driver input to receiver output. The four receivers each feature a built-in D-type latch that is controlled from the buffered receiver latch enable (\overline{RLE}) input. When the \overline{RLE} input is LOW, the latch is open and the receiver outputs will follow the bus inputs (BUS data inverted). When the \overline{RLE} input is HIGH, the latch will close and retain the present data regardless of the bus input.

The Am2906 features a built-in four-bit odd parity checker/generator. The bus enable input (\overline{BE}) controls whether the parity output is in the generate or check mode. When the bus enable is LOW (driver enabled), odd parity is generated based on the A or B field data input to the driver register. When \overline{BE} is HIGH, the parity output is determined by the four latch outputs of the receiver. Thus, if the driver is enabled, parity is generated and if the driver is in the high-impedance state, the BUS parity is checked.

LOGIC SYMBOL

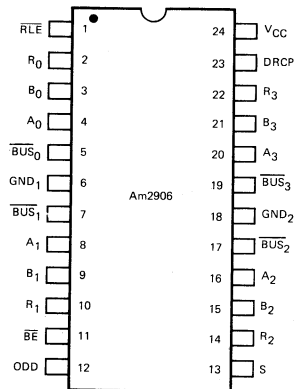


$V_{CC} = \text{Pin 24}$

$GND_1 = \text{Pin 6}$

$GND_2 = \text{Pin 18}$

CONNECTION DIAGRAM Top View

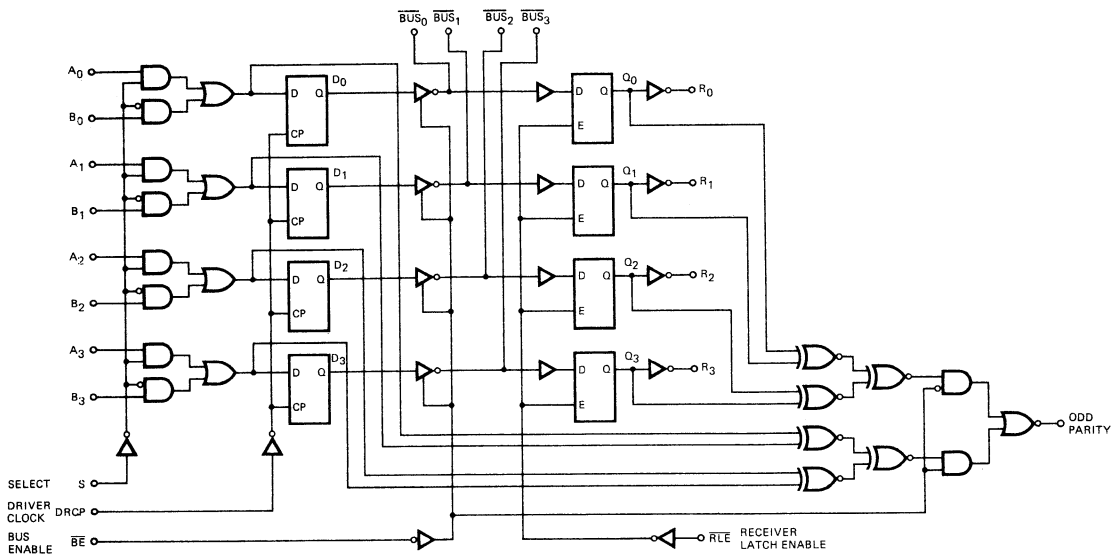


Note: Pin 1 is marked for orientation.

ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM2906PC
Hermetic DIP	0°C to +70°C	AM2906DC
Dice	0°C to +70°C	AM2906XC
Hermetic DIP	-55°C to +125°C	AM2906DM
Hermetic Flat Pak	-55°C to +125°C	AM2906FM
Dice	-55°C to +125°C	AM2906XM

LOGIC DIAGRAM



MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs (Except Bus)	30mA
DC Output Current, Into Bus	200mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2906XC (COM'L)	T _A = 0°C to +70°C	V _{CC} MIN. = 4.75V	V _{CC} MAX. = 5.25V
Am2906XM (MIL)	T _A = -55°C to +125°C	V _{CC} MIN. = 4.50V	V _{CC} MAX. = 5.50V

BUS INPUT/OUTPUT CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V _{OL}	Bus Output LOW Voltage	I _{OL} = 40mA		0.32	0.5	Volts	
			I _{OL} = 70mA		0.41		0.7
			I _{OL} = 100mA		0.55		0.8
I _O	Bus Leakage Current	V _{CC} = MAX.	V _O = 0.4V		-50	μA	
				V _O = 4.5V	MIL		
		COM'L			100		
I _{OFF}	Bus Leakage Current (Power OFF)	V _O = 4.5V			100	μA	
V _{TH}	Receiver Input HIGH Threshold	Bus enable = 2.4V	MIL	2.4	2.0	Volts	
			COM'L	2.3	2.0		
V _{TL}	Receiver Input LOW Threshold	Bus enable = 2.4V	MIL		2.0	Volts	
			COM'L		2.0		1.5
					1.6		

Am2906

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2906XC (COM'L) $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC\text{ MIN.}} = 4.75\text{V}$ $V_{CC\text{ MAX.}} = 5.25\text{V}$
 Am2906XM (MIL) $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC\text{ MIN.}} = 4.5\text{V}$ $V_{CC\text{ MAX.}} = 5.5\text{V}$

DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

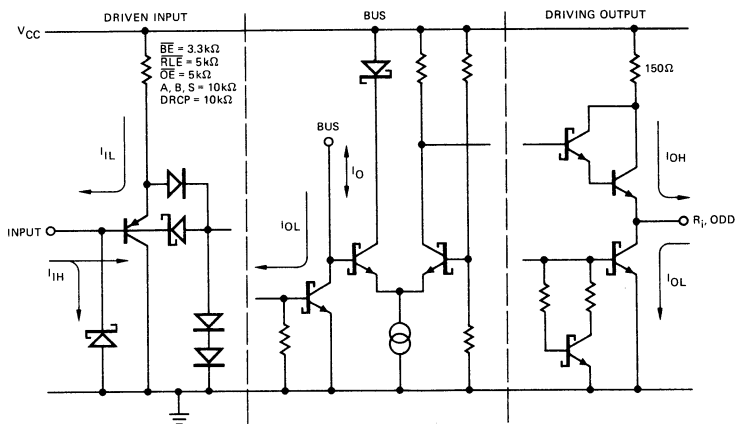
Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)		Units	
			Min.	Max.		
V_{OH}	Receiver Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IL} \text{ or } V_{IH}$	MIL 2.4	COM'L 3.4	Volts	
	Parity Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -660\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL 2.5	COM'L 3.4		
V_{OL}	Output LOW Voltage (Except Bus)	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IL} \text{ or } V_{IH}$	$I_{OL} = 4\text{mA}$	0.27	0.4	Volts
			$I_{OL} = 8\text{mA}$	0.32	0.45	
			$I_{OL} = 12\text{mA}$	0.37	0.5	
V_{IH}	Input HIGH Level (Except Bus)	Guaranteed input logical HIGH for all inputs	2.0		Volts	
V_{IL}	Input LOW Level (Except Bus)	Guaranteed input logical LOW for all inputs	MIL		0.7	Volts
			COM'L		0.8	
V_I	Input Clamp Voltage (Except Bus)	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{mA}$		-1.2	Volts	
I_{IL}	Input LOW Current (Except Bus)	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{V}$		-0.36	mA	
I_{IH}	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{V}$		20	μA	
I_I	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}, V_{IN} = 5.5\text{V}$		100	μA	
I_{SC}	Output Short Circuit Current (Except Bus)	$V_{CC} = \text{MAX.}$	-12	-65	mA	
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}, \text{All inputs} = \text{GND}$		72	105	mA

SWITCHING CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions	Am2906XM		Am2906XC		Units		
			Min.	Typ. (Note 2)	Max.	Min.		Typ. (Note 2)	Max.
t_{PHL}	Driver Clock (DRCP) to Bus	$C_L (\text{BUS}) = 50\text{pF}$ $R_L (\text{BUS}) = 50\Omega$		21	40		21	36	ns
t_{PLH}				21	40		21	36	
t_{PHL}	Bus Enable ($\overline{\text{BE}}$) to Bus			13	26		13	23	ns
t_{PLH}				13	26		13	23	
t_s	Data Inputs (A or B)		25			23			ns
t_h			8.0			7.0			
t_s	Select Inputs (S)		33			30			ns
t_h			8.0			7.0			
t_{PW}	Clock Pulse Width (HIGH)		28			25		ns	
t_{PLH}	Bus to Receiver Output (Latch Enabled)	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$		18	37		18	34	ns
t_{PHL}				18	37		18	34	
t_{PLH}	Latch Enable to Receiver Output			21	37		21	34	ns
t_{PHL}				21	37		21	34	
t_s	Bus to Latch Enable ($\overline{\text{RLE}}$)		21			18			ns
t_h			7.0			5.0			
t_{PLH}	A or B Data to Odd Parity Output (Driver Enabled)			21	40		21	36	ns
t_{PHL}				21	40		21	36	
t_{PLH}	Bus to Odd Parity Output (Driver Inhibited, Latch Enabled)			21	40		21	36	ns
t_{PHL}				21	40		21	36	
t_{PLH}	Latch Enable ($\overline{\text{RLE}}$) to Odd Parity Output			21	40		21	36	ns
t_{PHL}				21	40		21	36	

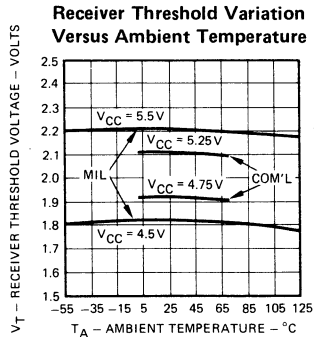
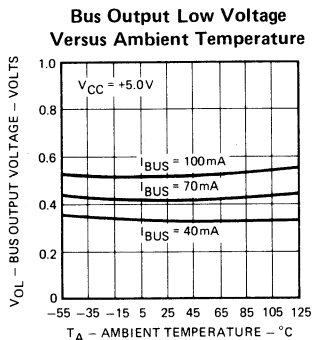
- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

INPUT/OUTPUT CURRENT INTERFACE CONDITIONS

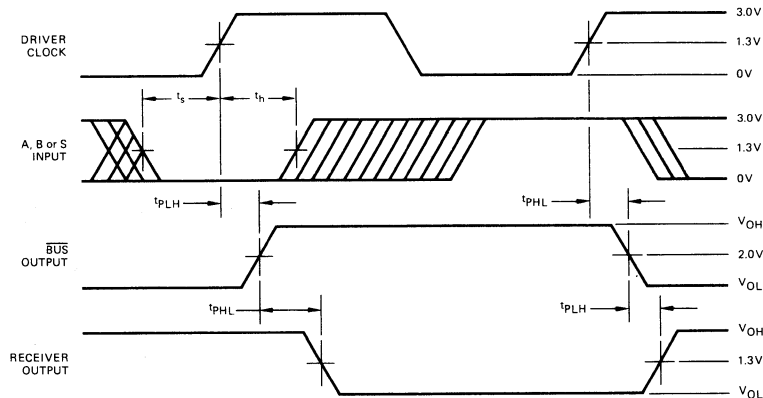


Note: Actual current flow direction shown.

TYPICAL PERFORMANCE CURVES



SWITCHING WAVEFORMS



Note: Bus to Receiver output delay is measured by clocking data into the driver register and measuring the BUS to R combinatorial delay.

3

FUNCTION TABLE

INPUTS							INTERNAL TO DEVICE		BUS	OUTPUT	FUNCTION
S	A _i	B _i	DRCP	\overline{BE}	\overline{RLE}	\overline{OE}	D _i	Q _i	\overline{BUS}_i	R _i	
X	X	X	X	H	X	X	X	X	Z	X	Driver output disable
X	X	X	X	X	X	H	X	X	X	Z	Receiver output disable
X	X	X	X	H	L	L	X	L	L	H	Driver output disable and receive data via Bus input
X	X	X	X	H	L	L	X	H	H	L	
X	X	X	X	X	H	X	X	NC	X	X	Latch received data
L	L	X	↑	X	X	X	L	X	X	X	Load driver register
L	H	X	↑	X	X	X	H	X	X	X	
H	X	L	↑	X	X	X	L	X	X	X	
H	X	H	↑	X	X	X	H	X	X	X	
X	X	X	L	X	X	X	NC	X	X	X	No driver clock restrictions
X	X	X	H	X	X	X	NC	X	X	X	
X	X	X	X	L	X	X	L	X	H	X	Drive Bus
X	X	X	X	L	X	X	H	X	L	X	

H = HIGH Z = HIGH Impedance X = Don't care i = 0, 1, 2, 3
 L = LOW NC = No change ↑ = LOW-to-HIGH transition

DEFINITION OF FUNCTIONAL TERMS

A₀, A₁, A₂, A₃ The "A" word data input into the two input multiplexer of the driver register.

B₀, B₁, B₂, B₃ The "B" word data input into the two input multiplexers of the driver register.

S Select. When the select input is LOW, the A data word is applied to the driver register. When the select input is HIGH, the B word is applied to the driver register.

DRCP Driver Clock Pulse. Clock pulse for the driver register.

\overline{BE} Bus Enable. When the Bus Enable is HIGH, the four drivers are in the high impedance state.

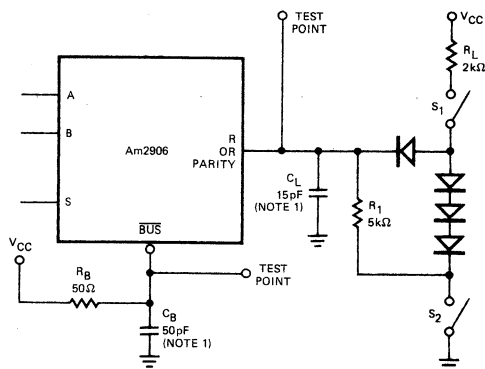
\overline{BUS}_0 , \overline{BUS}_1 , \overline{BUS}_2 , \overline{BUS}_3 The four driver outputs and receiver inputs (data is inverted).

R₀, R₁, R₂, R₃ The four receiver outputs. Data from the bus is inverted while data from the A or B inputs is non-inverted.

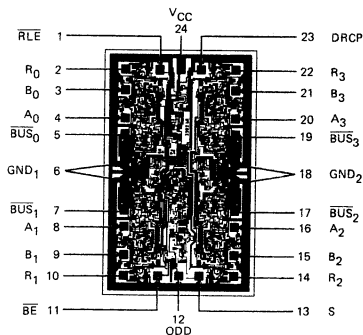
\overline{RLE} Receiver Latch Enable. When \overline{RLE} is LOW, data on the BUS inputs is passed through the receiver latches. When \overline{RLE} is HIGH, the receiver latches are closed and will retain the data independent of all other inputs.

\overline{OE} Output Enable. When the \overline{OE} input is HIGH, the four three state receiver outputs are in the high-impedance state.

LOAD TEST CIRCUIT

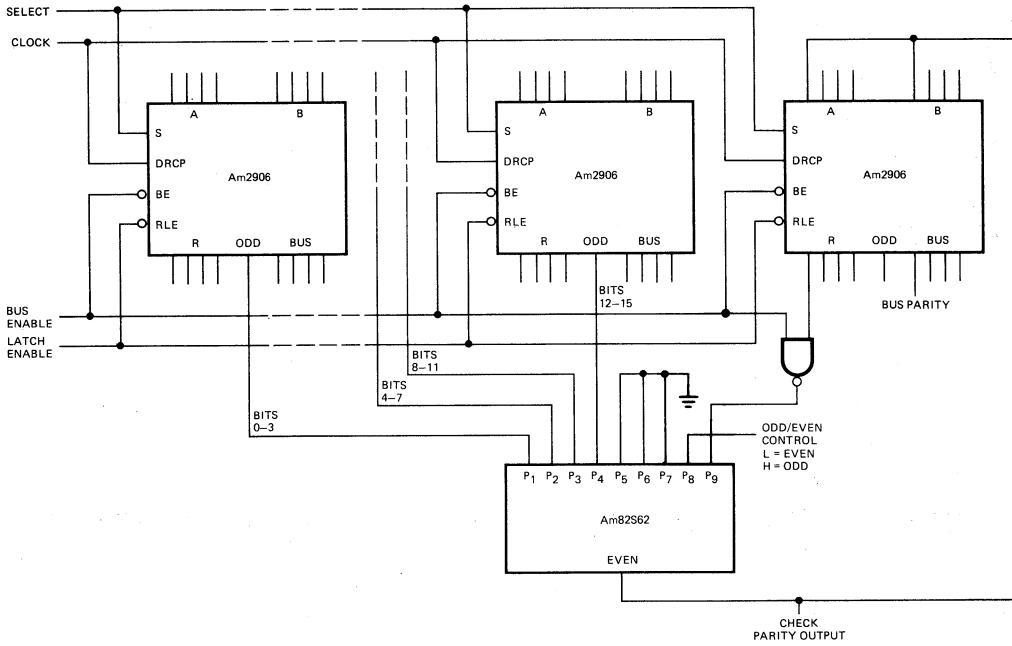


Metallization and Pad Layout



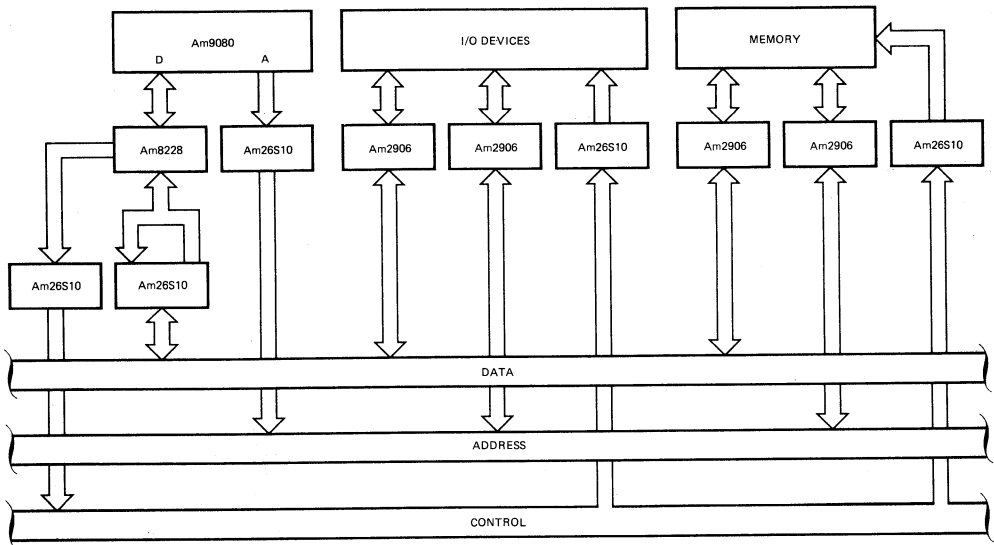
DIE SIZE 0.080" X 0.130"

APPLICATIONS



Generating or checking parity for 16 data bits.

3



Using the Am2906 and Am26S10 in a terminated Bus system for the Am9080 MOS Microprocessor.

Am2907

Quad Bus Transceiver With Three-State Receiver And Parity

Distinctive Characteristics

- Quad high-speed LSI bus-transceiver
- Open-collector bus driver
- D-type register on driver
- Bus driver output can sink 100 mA at 0.8 V max.
- Internal odd 4-bit parity checker/generator
- Receiver has output latch for pipeline operation
- Three-state receiver outputs sink 12 mA
- Advanced Low-Power Schottky processing
- 100% reliability assurance testing in compliance with MIL-STD-883

FUNCTIONAL DESCRIPTION

The Am2907 is a high-performance, low-power Schottky bus transceiver intended for bipolar or MOS microprocessor system applications. The device consists of four D-type edge-triggered flip-flops. The flip-flop outputs are connected to four open-collector bus drivers. Each bus driver is internally connected to one input of a differential amplifier in the receiver. The four receiver differential amplifier outputs drive four D-type latches, that feature three-state outputs. The device also contains a four-bit odd parity checker/generator.

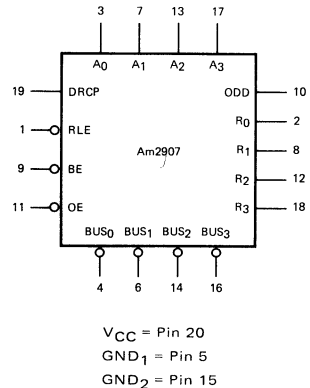
This LSI bus transceiver is fabricated using advanced low-power Schottky processing. All inputs (except the BUS inputs) are one LS unit load. The open-collector bus output can sink up to 100 mA at 0.8 V maximum. The BUS input differential amplifier contains disconnect protection diodes such that the bus is fail-safe when power is not applied. The bus enable input (\overline{BE}) is used to force the driver outputs to the high-impedance state. When \overline{BE} is HIGH, the driver is disabled. The open-collector structure of the driver allows wired-OR operations to be performed on the bus.

The input register consists of four D-type flip-flops with a buffered common clock. The buffered common clock (DRCP) enters the A_i data into this driver register on the LOW-to-HIGH transition.

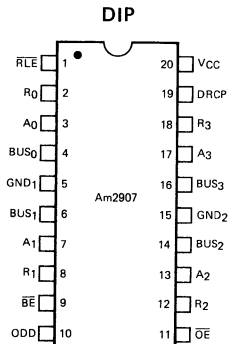
Data from the A input is inverted at the BUS output. Likewise, data at the BUS input is inverted at the receiver output. Thus, data is non-inverted from driver input to receiver output. The four receivers each feature a built-in D-type latch that is controlled from the buffered receiver latch enable (\overline{RLE}) input. When the \overline{RLE} input is LOW, the latch is open and the receiver outputs will follow the bus inputs (BUS data inverted and \overline{OE} LOW). When the \overline{RLE} input is HIGH, the latch will close and retain the present data regardless of the bus input. The four latches have three-state outputs and are controlled by a buffered common three-state control (\overline{OE}) input. When \overline{OE} is HIGH, the receiver outputs are in the high-impedance state.

The Am2907 features a built-in four-bit odd parity checker/generator. The bus enable input (\overline{BE}) controls whether the parity output is in the generate or check mode. When the bus enable is LOW (driver enabled), odd parity is generated based on the A field data input to the driver register. When \overline{BE} is HIGH, the parity output is determined by the four latch outputs of the receiver. Thus, if the driver is enabled, parity is generated and if the driver is in the high-impedance state, the BUS parity is checked.

LOGIC SYMBOL



CONNECTION DIAGRAMS Top Views

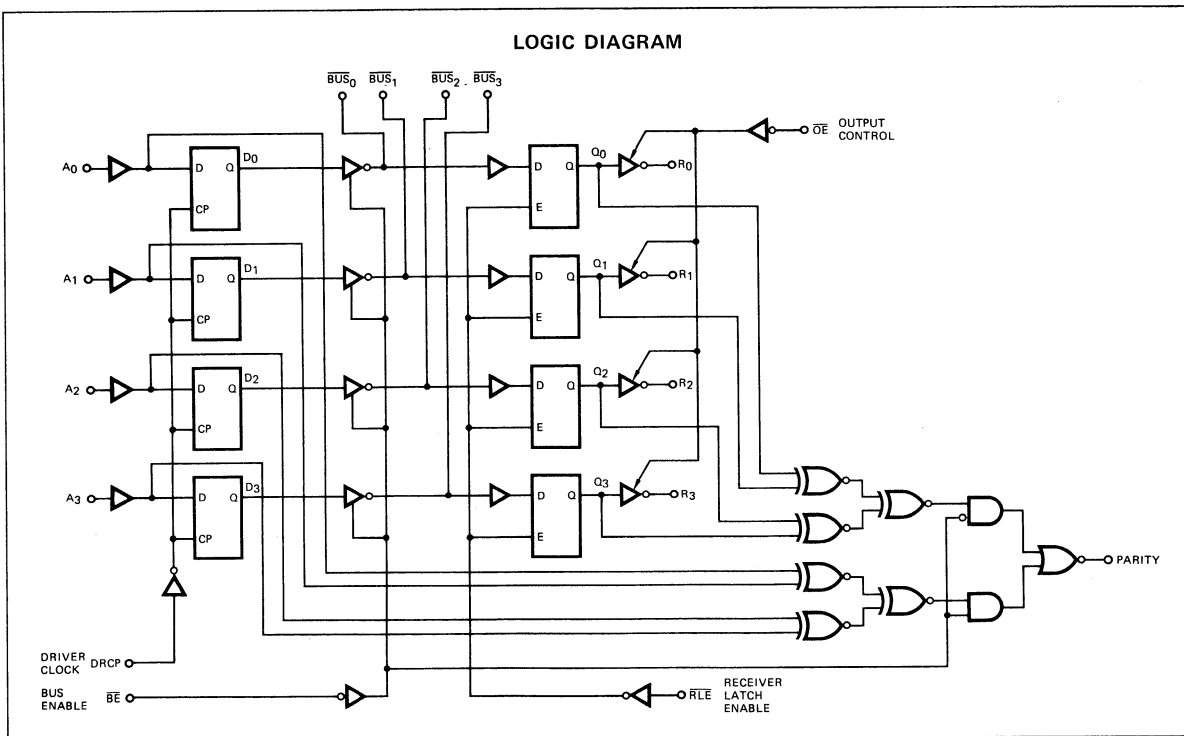


Note: Pin 1 is marked for orientation.

ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM2907PC
Hermetic DIP	0°C to +70°C	AM2907DC
Dice	0°C to +70°C	AM2907XC
Hermetic DIP	-55°C to +125°C	AM2907DM
* Hermetic Flat Pak	-55°C to +125°C	AM2907FM
Dice	-55°C to +125°C	AM2907XM

* Available on special order



3

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential	-0.5 V to +7 V
DC Voltage Applied to Outputs for HIGH Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +5.5 V
DC Output Current, Into Outputs (Except BUS)	30 mA
DC Output Current, Into Bus	200 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2907XC (COM'L)	T _A = 0°C to +70°C	V _{CC} MIN. = 4.75V	V _{CC} MAX. = 5.25V
Am2907XM (MIL)	T _A = -55°C to +125°C	V _{CC} MIN. = 4.50V	V _{CC} MAX. = 5.50V

BUS INPUT/OUTPUT CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OL}	Bus Output LOW Voltage	V _{CC} = MIN.	I _{OL} = 40mA	0.32	0.5	Volts
			I _{OL} = 70mA	0.41	0.7	
			I _{OL} = 100mA	0.55	0.8	
I _O	Bus Leakage Current	V _{CC} = MAX.	V _O = 0.4V		-50	μA
			V _O = 4.5V	MIL	200	
I _{OFF}	Bus Leakage Current (Power Off)	V _O = 4.5V			100	μA
V _{TH}	Receiver Input HIGH Threshold	Bus Enable = 2.4V	MIL	2.4	2.0	Volts
			COM'L	2.3	2.0	
V _{TL}	Receiver Input LOW Threshold	Bus Enable = 2.4V	MIL		2.0	Volts
			COM'L		2.0	

Am2907

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2907XC (COM'L) $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} \text{ MIN.} = 4.75\text{V}$ $V_{CC} \text{ MAX.} = 5.25\text{V}$
 Am2907XM (MIL) $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC} \text{ MIN.} = 4.50\text{V}$ $V_{CC} \text{ MAX.} = 5.50\text{V}$

DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

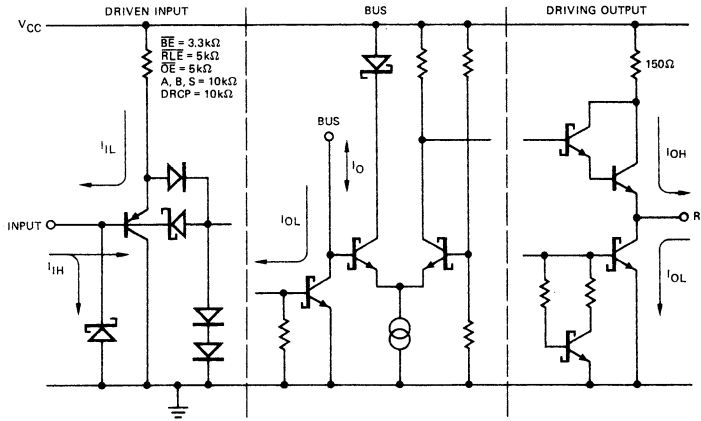
Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Receiver Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IL} \text{ or } V_{IH}$	MIL: $I_{OH} = -1\text{mA}$	2.4	3.4		Volts
			COM'L: $I_{OH} = -2.6\text{mA}$	2.4	3.4		
V_{OH}	Parity Output HIGH Voltage	$V_{CC} = \text{MIN.}$, $I_{OH} = -660\mu\text{A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage (Except Bus)	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IL} \text{ or } V_{IH}$	$I_{OL} = 4\text{mA}$		0.27	0.4	Volts
			$I_{OL} = 8\text{mA}$		0.32	0.45	
			$I_{OL} = 12\text{mA}$		0.37	0.5	
V_{IH}	Input HIGH Level (Except Bus)	Guaranteed input logical HIGH for all inputs		2.0			Volts
V_{IL}	Input LOW Level (Except Bus)	Guaranteed input logical LOW for all inputs		MIL		0.7	Volts
				COM'L		0.8	
V_I	Input Clamp Voltage (Except Bus)	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$				-1.2	Volts
I_{IL}	Input LOW Current (Except Bus)	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$				-0.36	mA
I_{IH}	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$				20	μA
I_I	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}$, $V_{IN} = 5.5\text{V}$				100	μA
I_{SC}	Output Short Circuit Current (Except Bus)	$V_{CC} = \text{MAX.}$		-12		-65	mA
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$, All Inputs = GND			75	110	mA
I_O	Off-State Output Current (Receiver Outputs)	$V_{CC} = \text{MAX.}$		$V_O = 2.4\text{V}$		20	μA
				$V_O = 0.4\text{V}$		-20	

SWITCHING CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions	Am2907XM		Am2907XC		Units		
			Min.	Typ. (Note 2)	Max.	Min.		Typ. (Note 2)	Max.
t_{PHL}	Driver Clock (DRCP) to Bus	$C_L \text{ (BUS)} = 50\text{pF}$ $R_L \text{ (BUS)} = 50\Omega$		21	40		21	36	ns
t_{PLH}				21	40		21	36	
t_{PHL}	Bus Enable (\overline{BE}) to Bus			13	26		13	23	ns
t_{PLH}				13	26		13	23	
t_s	A Data Inputs			25			23		ns
t_h				8.0			7.0		
t_{PW}	Clock Pulse Width (HIGH)			28			25		ns
t_{PLH}	Bus to Receiver Output (Latch Enabled)			18	37		18	34	ns
t_{PHL}				18	37		18	34	
t_{PLH}	Latch Enable to Receiver Output			21	37		21	34	ns
t_{PHL}				21	37		21	34	
t_s	Bus to Latch Enable (\overline{RLE})	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$		21			18		ns
t_h				7.0			5.0		
t_{PLH}	A Data to Odd Parity Out (Driver Enabled)			21	40		21	36	ns
t_{PHL}				21	40		21	36	
t_{PLH}	Bus to Odd Parity Out (Driver Inhibit)			21	40		21	36	ns
t_{PHL}				21	40		21	36	
t_{PLH}	Latch Enable (\overline{RLE}) to Odd Parity Output			21	40		21	36	ns
t_{PHL}				21	40		21	36	
t_{ZH}	Output Control to Output			14	28		14	25	ns
t_{ZL}				14	28		14	25	
t_{HZ}	Output Control to Output	$C_L = 5.0\text{pF}$ $R_L = 2.0\text{k}\Omega$		14	28		14	25	ns
t_{LZ}				14	28		14	25	

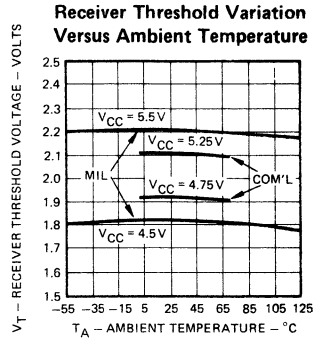
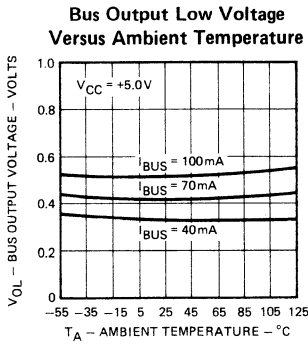
- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

INPUT/OUTPUT CURRENT INTERFACE CONDITIONS

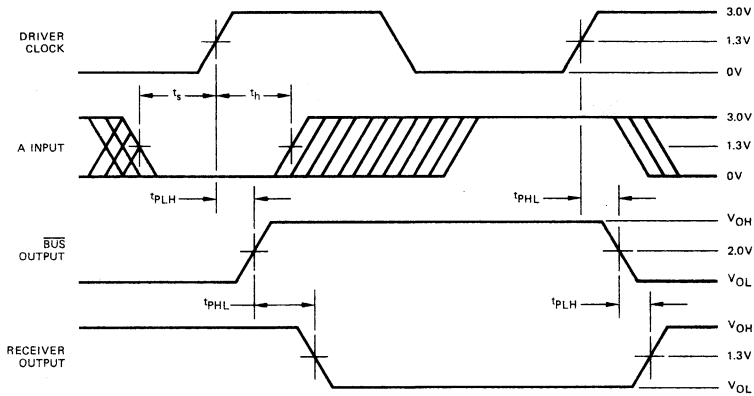


Note: Actual current flow direction shown.

TYPICAL PERFORMANCE CURVES



SWITCHING WAVEFORMS



Note: Bus to Receiver output delay is measured by clocking data into the driver register and measuring the BUS to R combinatorial delay.

3

TRUTH TABLE

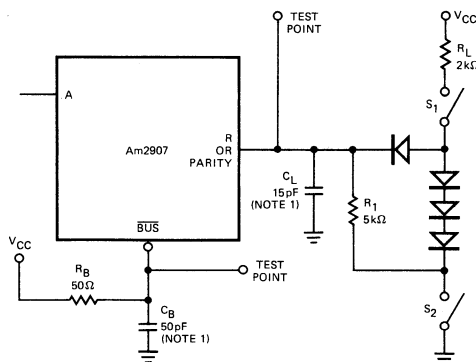
INPUTS					INTERNAL TO DEVICE		BUS	OUTPUT	FUNCTION
A _i	DRCP	\overline{BE}	\overline{RLE}	\overline{OE}	D _i	Q _i	B _i	R _i	
X	X	H	X	X	X	X	H	X	Driver output disable
X	X	X	X	H	X	X	X	Z	Receiver output disable
X	X	H	L	L	X	L	L	H	Driver output disable and receive data via Bus input
X	X	H	L	L	X	H	H	L	
X	X	X	H	X	X	NC	X	X	Latch received data
L	↑	X	X	X	L	X	X	X	Load driver register
H	↑	X	X	X	H	X	X	X	
X	L	X	X	X	NC	X	X	X	No driver clock restrictions
X	H	X	X	X	NC	X	X	X	
X	X	L	X	X	L	X	H	X	Drive Bus
X	X	L	X	X	H	X	L	X	

H = HIGH Z = High Impedance X = Don't Care i = 0, 1, 2, 3
 L = LOW NC = No Change ↑ = LOW-to-HIGH Transition

PARITY OUTPUT FUNCTION TABLE

\overline{BE}	ODD PARITY OUTPUT
L	ODD = A ₀ ⊕ A ₁ ⊕ A ₂ ⊕ A ₃
H	ODD = Q ₀ ⊕ Q ₁ ⊕ Q ₂ ⊕ Q ₃

LOAD TEST CIRCUIT



DEFINITION OF FUNCTIONAL TERMS

DRCP Driver Clock Pulse. Clock pulse for the driver register.

\overline{BE} Bus Enable. When the Bus Enable is LOW, the four drivers are in the high impedance state.

BUS₀, BUS₁, BUS₂, BUS₃ The four driver outputs and receiver inputs (data is inverted).

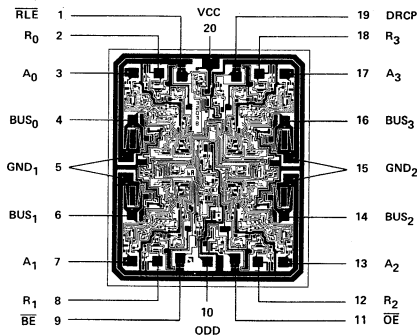
R₀, R₁, R₂, R₃ The four receiver outputs. Data from the bus is inverted while data from the A or B inputs is non-inverted.

\overline{RLE} Receiver Latch Enable. When \overline{RLE} is LOW, data on the BUS inputs is passed through the receiver latches. When \overline{RLE} is HIGH, the receiver latches are closed and will retain the data independent of all other inputs.

ODD Odd parity output. Generates parity with the driver enabled, checks parity with the driver in the high-impedance state.

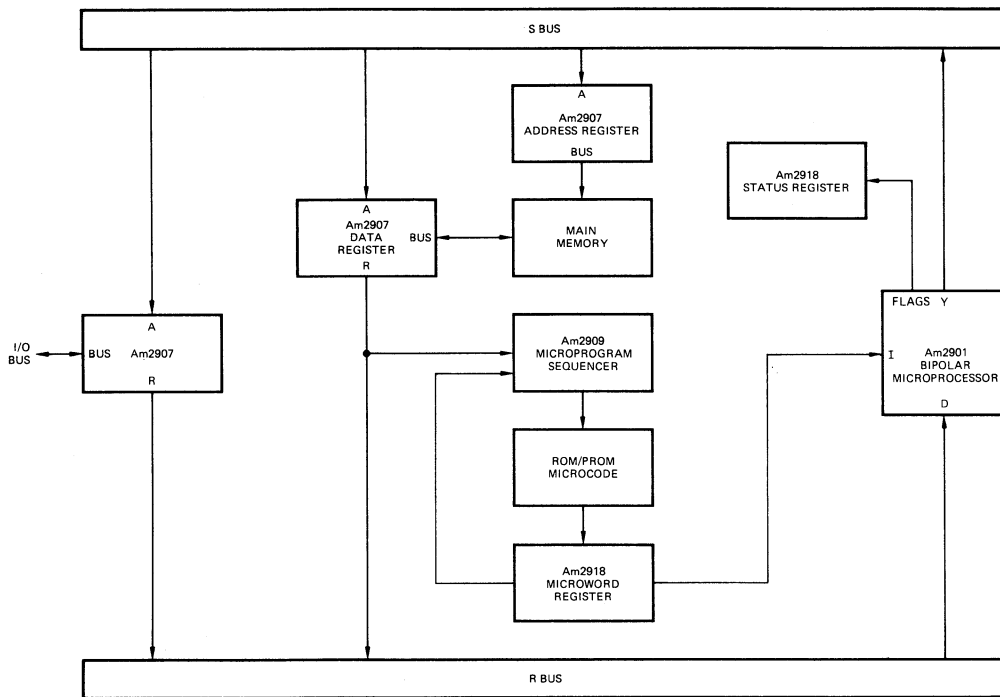
\overline{OE} Output Enable. When the \overline{OE} input is HIGH, the four three-state receiver outputs are in the high-impedance state.

Metallization and Pad Layout

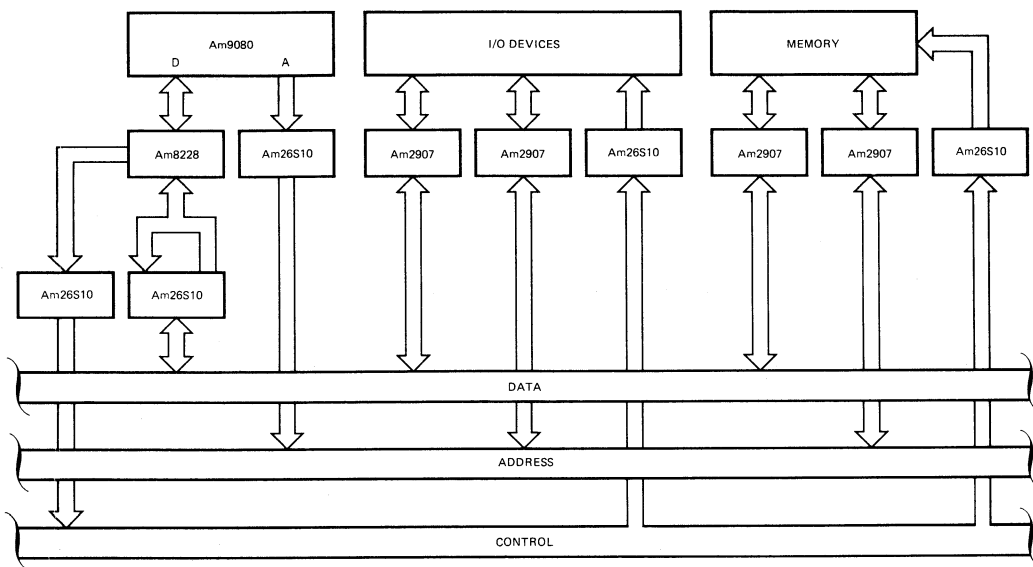


DIE SIZE 0.088'' X 0.103''

APPLICATIONS



The Am2907 can be used as an I/O Bus Transceiver and Main Memory I/O Transceiver in high-speed Microprocessor Systems.



Using the Am2907 and Am26S10 in a terminated Bus system for the Am9080 MOS Microprocessor.

3

Am2915A

Quad Three-State Bus Transceiver With Interface Logic

Distinctive Characteristics

- Quad high-speed LSI bus-transceiver
- Three-state bus driver
- Two-port input to D-type register on driver
- Bus driver output can sink 48mA at 0.5V max.
- Receiver has output latch for pipeline operation
- Three-state receiver outputs sink 12mA
- Advanced low-power Schottky processing
- 100% reliability assurance testing in compliance with MIL-STD-883
- 3.5V minimum output high voltage for direct interface to MOS microprocessors

FUNCTIONAL DESCRIPTION

The Am2915A is a high-performance, low-power Schottky bus transceiver intended for bipolar or MOS microprocessor system applications. The device consists of four D-type edge-triggered flip-flops with a built-in two-input multiplexer on each. The flip-flop outputs are connected to four three-state bus drivers. Each bus driver is internally connected to the input of a receiver. The four receiver outputs drive four D-type latches that feature three-state outputs.

This LSI bus transceiver is fabricated using advanced low-power Schottky processing. All inputs (except the BUS inputs) are one LS unit load. The three-state bus output can sink up to 48mA at 0.5V maximum. The bus enable input (BE) is used to force the driver outputs to the high-impedance state. When \overline{BE} is HIGH, the driver is disabled. The V_{OH} and V_{OL} of the bus driver are selected for compatibility with standard and Low-Power Schottky inputs.

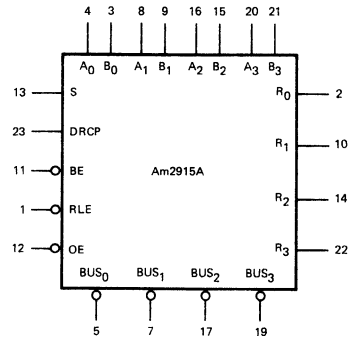
The input register consists of four D-type flip-flops with a buffered common clock and a two-input multiplexer at the input of each flip-flop. A common select input (S) controls the four multiplexers. When S is LOW, the A_i data is stored in the register and when S is HIGH, the B_i data is stored. The buffered common clock (DRCP) enters the data into this driver register on the LOW-to-HIGH transition.

Data from the A or B inputs is inverted at the BUS output. Likewise, data at the BUS input is inverted at the receiver output. Thus, data is non-inverted from driver input to receiver output. The four receivers each feature a built-in D-type latch that is controlled from the buffered receiver latch enable (RLE) input. When the RLE input is LOW, the latch is open and the receiver outputs will follow the bus inputs (BUS data inverted and OE LOW). When the RLE input is HIGH, the latch will close and retain the present data regardless of the bus input. The four latches have three-state outputs and are controlled by a buffered common three-state control (\overline{OE}) input. When \overline{OE} is HIGH, the receiver outputs are in the high-impedance state.

ORDERING INFORMATION

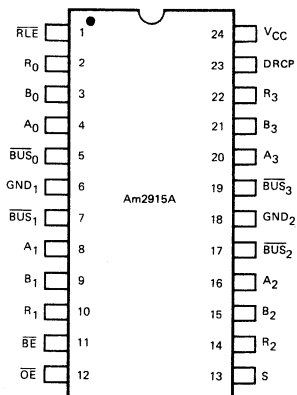
Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM2915APC
Hermetic DIP	0°C to +70°C	AM2915ADC
Dice	0°C to +70°C	AM2915AXC
Hermetic DIP	-55°C to +125°C	AM2915ADM
Hermetic Flat Pak	-55°C to +125°C	AM2915AFM
Dice	-55°C to +125°C	AM2915AXM

LOGIC SYMBOL



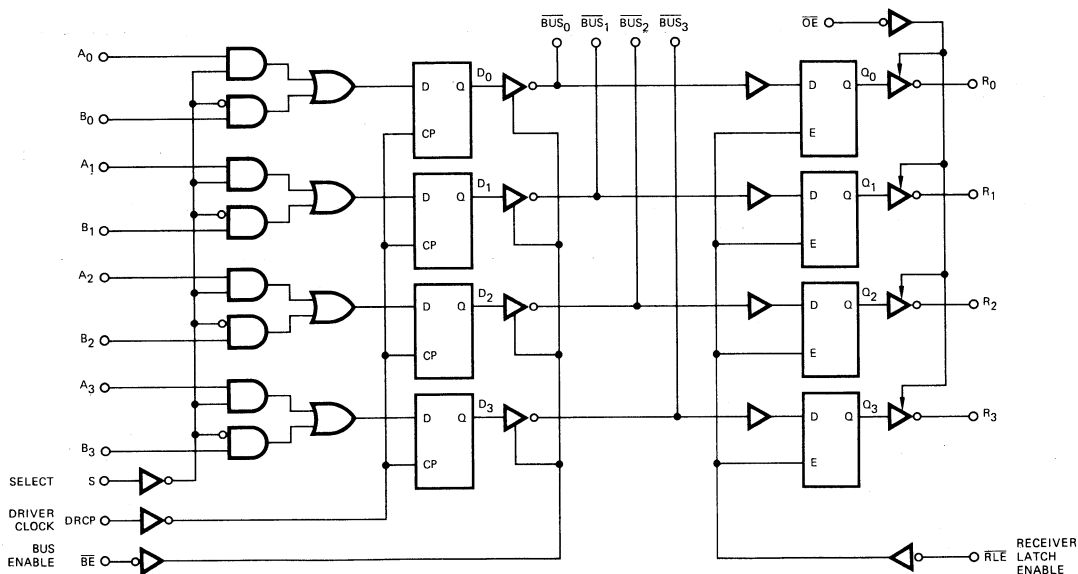
V_{CC} = Pin 24
 GND_1 = Pin 6
 GND_2 = Pin 18

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC DIAGRAM



MPR-161

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7V
DC Output Current, Into Outputs (Except Bus)	30mA
DC Output Current, Into Bus	100mA
DC Input Current	-30mA to +5.0mA

3

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2915AXC (COM'L)	T _A = 0°C to +70°C	V _{CC} MIN. = 4.75V	V _{CC} MAX. = 5.25V
Am2915AXM (MIL)	T _A = -55°C to +125°C	V _{CC} MIN. = 4.50V	V _{CC} MAX. = 5.50V

BUS INPUT/OUTPUT CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ.	Max.	Units
V _{OL}	Bus Output LOW Voltage	V _{CC} = MIN.	I _{OL} = 24mA		0.4	Volts
			I _{OL} = 48mA		0.5	
V _{OH}	Bus Output HIGH Voltage	V _{CC} = MIN.	COM'L, I _{OH} = -20mA	2.4		Volts
			MIL, I _{OH} = -15mA			
I _O	Bus Leakage Current (High Impedance)	V _{CC} = MAX. Bus enable = 2.4V	V _O = 0.4V		-200	μA
			V _O = 2.4V		50	
			V _O = 4.5V		100	
I _{OFF}	Bus Leakage Current (Power OFF)	V _O = 4.5V V _{CC} = 0V			100	μA
V _{IH}	Receiver Input HIGH Threshold	Bus enable = 2.4V	2.0			Volts
V _{IL}	Receiver Input LOW Threshold	Bus enable = 2.4V	COM'L		0.8	Volts
			MIL		0.7	
I _{SC}	Bus Output Short Circuit Current	V _{CC} = MAX. V _O = 0V	-50	-120	-225	mA

Am2915A

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2915AXC (COM'L) $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC\text{ MIN.}} = 4.75\text{ V}$ $V_{CC\text{ MAX.}} = 5.25\text{ V}$
 Am2915AXM (MIL) $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC\text{ MIN.}} = 4.50\text{ V}$ $V_{CC\text{ MAX.}} = 5.50\text{ V}$

DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

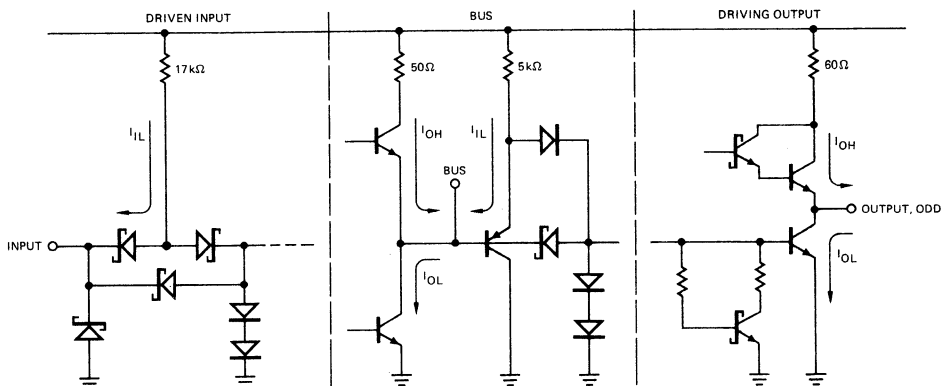
Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Receiver Output HIGH Voltage	$V_{CC} = \text{MIN.}$	MIL: $I_{OH} = -1.0\text{ mA}$	2.4	3.4		Volts
		$V_{IN} = V_{IL}$ or V_{IH}	COM'L: $I_{OH} = -2.6\text{ mA}$	2.4	3.4		
		$V_{CC} = 5.0\text{ V}, I_{OH} = -100\mu\text{ A}$		3.5			
V_{OL}	Output LOW Voltage (Except Bus)	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IL}$ or V_{IH}	$I_{OL} = 4.0\text{ mA}$		0.27	0.4	Volts
			$I_{OL} = 8.0\text{ mA}$		0.32	0.45	
			$I_{OL} = 12\text{ mA}$		0.37	0.5	
V_{IH}	Input HIGH Level (Except Bus)	Guaranteed input logical HIGH for all inputs		2.0			Volts
V_{IL}	Input LOW Level (Except Bus)	Guaranteed input logical LOW for all inputs	MIL			0.7	Volts
			COM'L			0.8	
V_I	Input Clamp Voltage (Except Bus)	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{ mA}$				-1.2	Volts
I_{IL}	Input LOW Current (Except Bus)	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{ V}$	$\overline{BE}, \overline{RLE}$			-0.72	mA
			All other inputs			-0.36	
I_{IH}	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{ V}$				20	$\mu\text{ A}$
I_I	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{ V}$				100	$\mu\text{ A}$
I_{SC}	Output Short Circuit Current (Except Bus)	$V_{CC} = \text{MAX.}$		-30		-130	mA
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$			63	95	mA
I_O	Off-State Output Current (Receiver Outputs)	$V_{CC} = \text{MAX.}$	$V_O = 2.4\text{ V}$			50	$\mu\text{ A}$
			$V_O = 0.4\text{ V}$			-50	

SWITCHING CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions	Am2915AXM			Am2915AXC			Units
			Min.	Typ. (Note 2)	Max.	Min.	Typ. (Note 2)	Max.	
t_{PHL}	Driver Clock (DRCP) to Bus	C_L (BUS) = 50pF R_L (BUS) = 130 Ω		21	36		21	32	ns
t_{PLH}				21	36		21	32	
t_{ZH}, t_{ZL}	Bus Enable (\overline{BE}) to Bus			13	26		13	23	ns
t_{HZ}, t_{LZ}				13	21		13	18	
t_s	Data Inputs (A or B)	$C_L = 15\text{ pF}$ $R_L = 2.0\text{ k}\Omega$		15			12		ns
t_h				8.0			6.0		
t_s	Select Input (S)			28			25		ns
t_h				8.0			6.0		
t_{PW}	Driver Clock (DRCP) Pulse Width (HIGH)			20			17		ns
t_{PLH}	Bus to Receiver Output (Latch Enable)			18	33		18	30	ns
t_{PHL}				18	30		18	27	
t_{PLH}	Latch Enable to Receiver Output			21	33		21	30	ns
t_{PHL}				21	30		21	27	
t_s	Bus to Latch Enable (\overline{RLE})			15			13		ns
t_h				6.0			4.0		
t_{ZH}, t_{ZL}	Output Control to Receiver Output		$C_L = 5\text{ pF}, R_L = 2.0\text{ k}\Omega$		14	26		14	23
t_{HZ}, t_{LZ}				14	26		14	23	

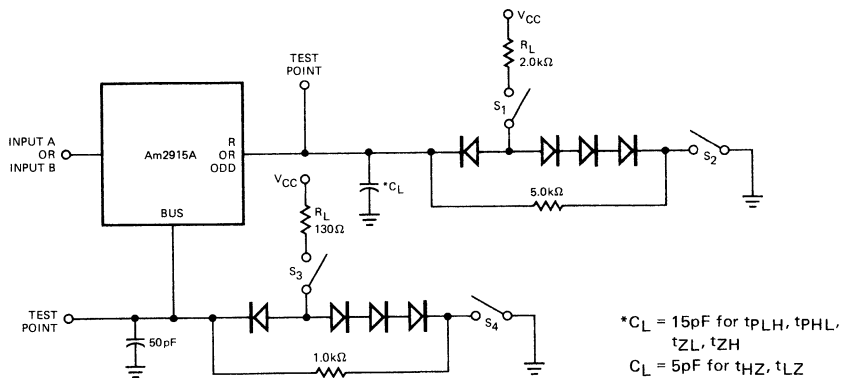
- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{ V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

INPUT/OUTPUT CURRENT INTERFACE CONDITIONS

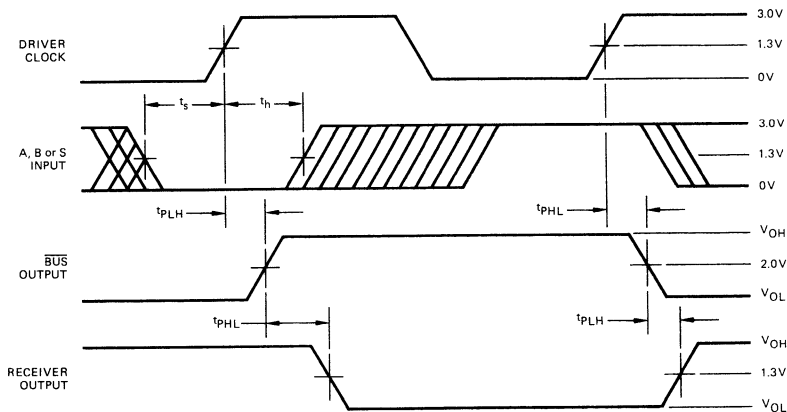


Note: Actual current flow direction shown.

SWITCHING TEST CIRCUIT



SWITCHING WAVEFORMS



Note: Bus to Receiver output delay is measured by clocking data into the driver register and measuring the BUS to R combinatorial delay.

3

FUNCTIONAL TABLE

INPUTS							INTERNAL TO DEVICE		BUS	OUTPUT	FUNCTION
S	A _i	B _i	DRCP	\overline{BE}	RLE	\overline{OE}	D _i	Q _i	\overline{BUS}_i	R _i	
X	X	X	X	H	X	X	X	X	Z	X	Driver output disable
X	X	X	X	X	X	H	X	X	X	Z	Receiver output disable
X	X	X	X	H	L	L	X	L	L	H	Driver output disable and receive data via Bus input
X	X	X	X	H	L	L	X	H	H	L	Driver output disable and receive data via Bus input
X	X	X	X	X	H	X	X	NC	X	X	Latch received data
L	L	X	↑	X	X	X	L	X	X	X	Load driver register
L	H	X	↑	X	X	X	H	X	X	X	
H	X	L	↑	X	X	X	L	X	X	X	
H	X	H	↑	X	X	X	H	X	X	X	
X	X	X	L	X	X	X	NC	X	X	X	No driver clock restrictions
X	X	X	H	X	X	X	NC	X	X	X	
X	X	X	X	L	X	X	L	X	H	X	Drive Bus
X	X	X	X	L	X	X	H	X	L	X	

H = HIGH
L = LOW

Z = HIGH Impedance
NC = No Change

X = Don't Care
↑ = LOW-to-HIGH Transition

i = 0, 1, 2, 3

DEFINITION OF FUNCTIONAL TERMS

A₀, A₁, A₂, A₃ The "A" word data input into the two input multiplexer of the driver register.

B₀, B₁, B₂, B₃ The "B" word data input into the two input multiplexers of the driver register.

S Select. When the select input is LOW, the A data word is applied to the driver register. When the select input is HIGH, the B word is applied to the driver register.

DRCP Driver Clock Pulse. Clock pulse for the driver register.

\overline{BE} Bus Enable. When the Bus Enable is HIGH, the four drivers are in the high impedance state.

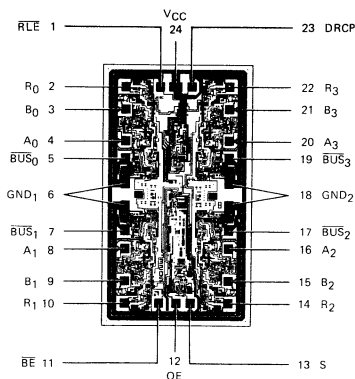
$\overline{BUS}_0, \overline{BUS}_1, \overline{BUS}_2, \overline{BUS}_3$ The four driver outputs and receiver inputs (data is inverted).

R₀, R₁, R₂, R₃ The four receiver outputs. Data from the bus is inverted while data from the A or B inputs is non-inverted.

RLE Receiver Latch Enable. When RLE is LOW, data on the BUS inputs is passed through the receiver latches. When RLE is HIGH, the receiver latches are closed and will retain the data independent of all other inputs.

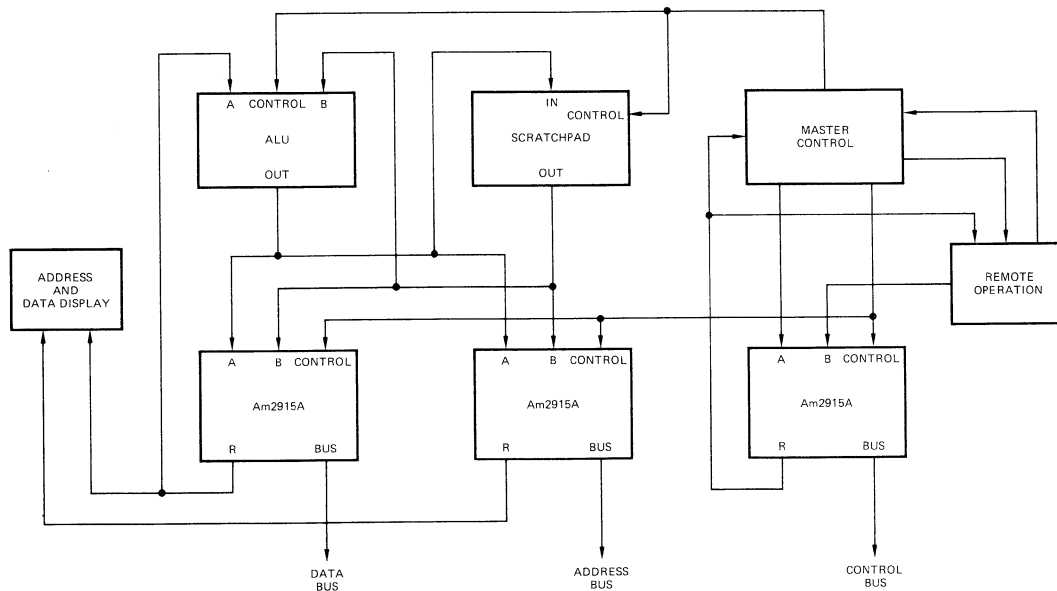
\overline{OE} Output Enable. When the \overline{OE} input is HIGH, the four three state receiver outputs are in the high-impedance state.

Metallization and Pad Layout



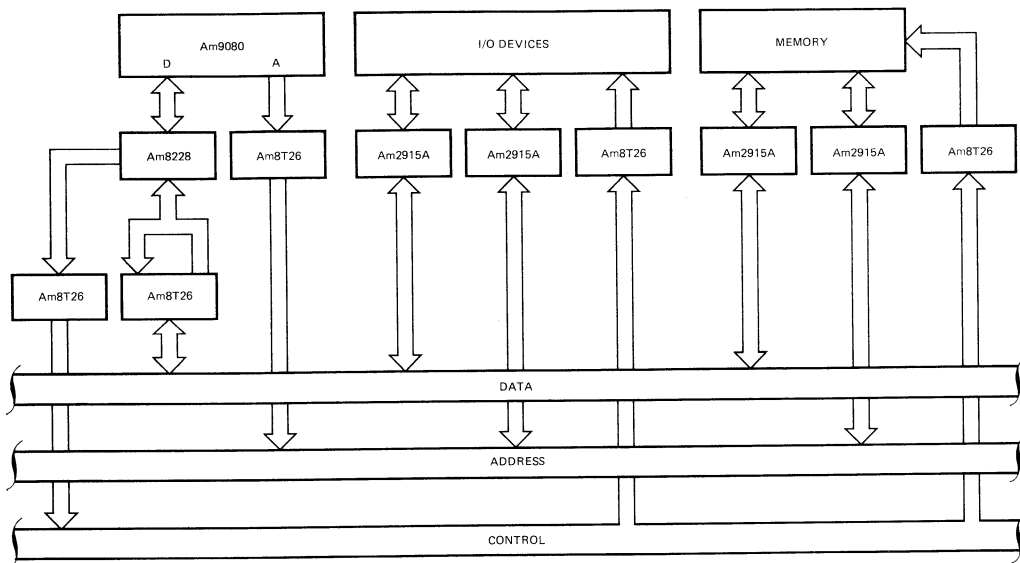
DIE SIZE .074" X .130"

APPLICATIONS



The Am2915A is a universal Bus Transceiver useful for many system data, address, control and timing input/output interfaces.

3



Using the Am2915A and Am8T26 in a terminated Bus system for the Am9080 MOS Microprocessor.

Am2916A

Quad Three-State Bus Transceiver With Interface Logic

Distinctive Characteristics

- Quad high-speed LSI bus-transceiver
- Three-state bus driver
- Two-port input to D-type register on driver
- Bus driver output can sink 48mA at 0.5V max.
- Internal odd 4-bit parity checker/generator
- Receiver has output latch for pipeline operation
- Receiver outputs sink 12mA
- Advanced low-power Schottky processing
- 100% reliability assurance testing in compliance with MIL-STD-883
- 3.5V minimum output high voltage for direct interface to MOS microprocessors

FUNCTIONAL DESCRIPTION

The Am2916A is a high-performance, low-power Schottky bus transceiver intended for bipolar or MOS microprocessor system applications. The device consists of four D-type edge-triggered flip-flops with a built-in two-input multiplexer on each. The flip-flop outputs are connected to four three-state bus drivers. Each bus driver is internally connected to the input of a receiver. The four receiver outputs drive four D-type latches. The device also contains a four-bit odd parity checker/generator.

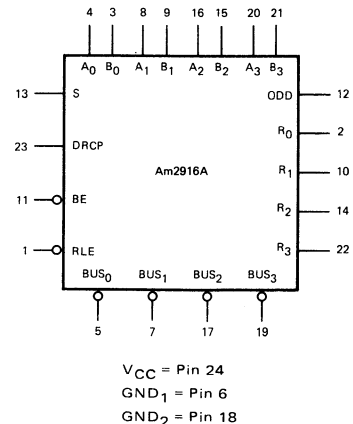
The LSI bus transceiver is fabricated using advanced low-power Schottky processing. All inputs (except the BUS inputs) are one LS unit load. The three-state bus output can sink up to 48mA at 0.5V maximum. The bus enable input (\overline{BE}) is used to force the driver outputs to the high-impedance state. When \overline{BE} is HIGH, the driver is disabled.

The input register consists of four D-type flip-flops with a buffered common clock and a two-input multiplexer at the input of each flip-flop. A common select input (S) controls the four multiplexers. When S is LOW, the A_i data is stored in the register and when S is HIGH, the B_i data is stored. The buffered common clock (DRCP) enters the data into this driver register on the LOW-to-HIGH transition.

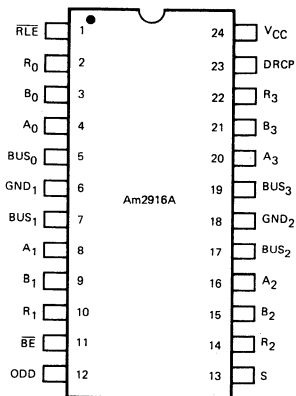
Data from the A or B input is inverted at the BUS output. Likewise, data at the BUS input is inverted at the receiver output. Thus, data in non-inverted from driver input to receiver output. The four receivers each feature a built-in D-type latch that is controlled from the buffered receiver latch enable (\overline{RLE}) input. When the \overline{RLE} input is LOW, the latch is open and the receiver outputs will follow the bus inputs (BUS data inverted). When the \overline{RLE} input is HIGH, the latch will close and retain the present data regardless of the bus input.

The Am2916A features a built-in four-bit odd parity checker/generator. The bus enable input (\overline{BE}) controls whether the parity output is in the generate or check mode. When the bus enable is LOW (driver enabled), odd parity is generated based on the A or B field data input to the driver register. When \overline{BE} is HIGH, the parity output is determined by the four latch outputs of the receiver. Thus, if the driver is enabled, parity is generated and if the driver is in the high-impedance state, the BUS parity is checked.

LOGIC SYMBOL



CONNECTION DIAGRAM Top View

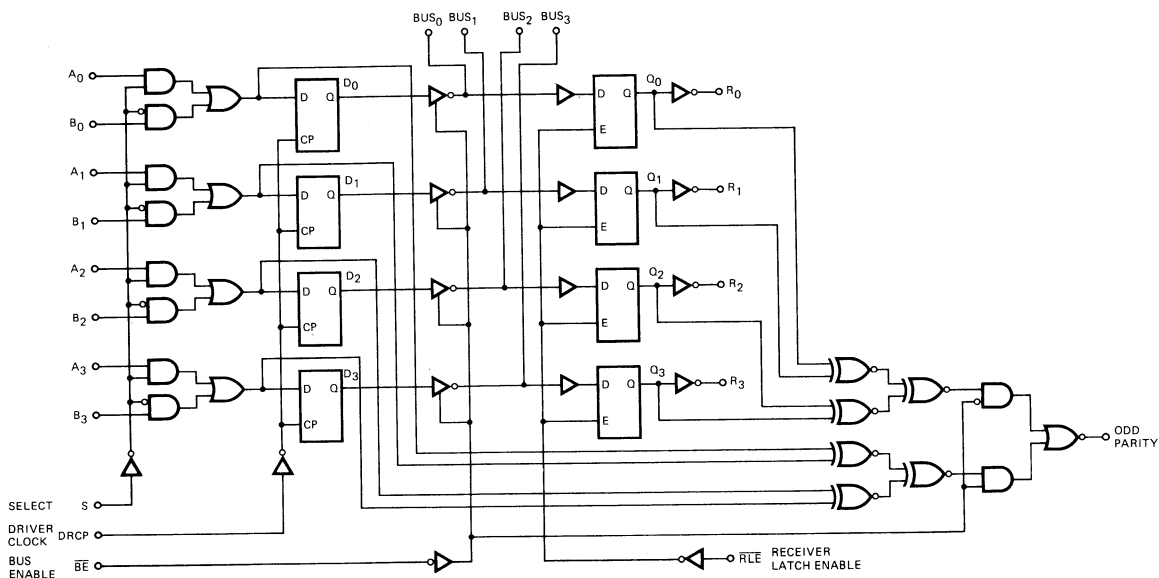


Note: Pin 1 is marked for orientation.

ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM2916APC
Hermetic DIP	0°C to +70°C	AM2916ADC
Dice	0°C to +70°C	AM2916AXC
Hermetic DIP	-55°C to +125°C	AM2916ADM
Hermetic Flat Pak	-55°C to +125°C	AM2916AFM
Dice	-55°C to +125°C	AM2916AXM

LOGIC DIAGRAM



MPR-169

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7V
DC Output Current, Into Outputs (Except Bus)	30mA
DC Output Current, Into Bus	100mA
DC Input Current	-30mA to +5.0mA

3

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2916AXC (COM'L) T_A = 0°C to +70°C V_{CC} MIN. = 4.75V V_{CC} MAX. = 5.25V
 Am2916AXM (MIL) T_A = -55°C to +125°C V_{CC} MIN. = 4.50V V_{CC} MAX. = 5.50V

BUS INPUT/OUTPUT CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ.	Max.	Units
V _{OL}	Bus Output LOW Voltage	V _{CC} = MIN.	I _{OL} = 24mA		0.4	Volts
			I _{OL} = 48mA		0.5	
V _{OH}	Bus Output HIGH Voltage	V _{CC} = MIN.	COM'L, I _{OH} = -20mA	2.4		Volts
			MIL, I _{OH} = -15mA			
I _O	Bus Leakage Current (High Impedance)	V _{CC} = MAX. Bus enable = 2.4V	V _O = 0.4V		-200	μA
			V _O = 2.4V		50	
			V _O = 4.5V		100	
I _{OFF}	Bus Leakage Current (Power OFF)	V _O = 4.5V V _{CC} = 0V			100	μA
V _{IH}	Receiver Input HIGH Threshold	Bus enable = 2.4V	2.0			Volts
V _{IL}	Receiver Input LOW Threshold	Bus enable = 2.4V	COM'L		0.8	Volts
			MIL		0.7	
I _{SC}	Bus Output Short Circuit Current	V _{CC} = MAX. V _O = 0V	-50	-120	-225	mA

Am2916A

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2916AXC (COM'L) $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC\text{MIN.}} = 4.75\text{V}$ $V_{CC\text{MAX.}} = 5.25\text{V}$
 Am2916AXM (MIL) $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC\text{MIN.}} = 4.50\text{V}$ $V_{CC\text{MAX.}} = 5.50\text{V}$

DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

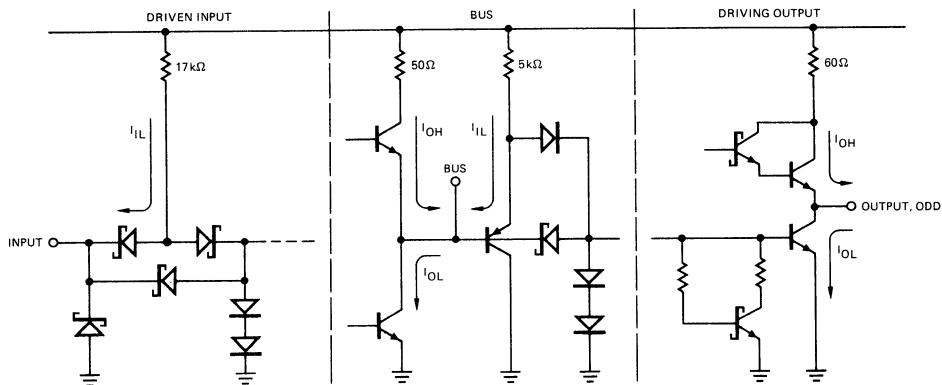
Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Receiver Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IL}$ or V_{IH}	MIL: $I_{OH} = -1.0\text{mA}$	2.4	3.4		Volts
			COM'L: $I_{OH} = -2.6\text{mA}$	2.4	3.4		
		$V_{CC} = 5.0\text{V}$, $I_{OH} = -100\mu\text{A}$	3.5				
V_{OH}	Parity Output HIGH Voltage	$V_{CC} = \text{MIN.}$, $I_{OH} = -660\mu\text{A}$ $V_{IN} = V_{IH}$ or V_{IL}	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage (Except Bus)	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IL}$ or V_{IH}	$I_{OL} = 4.0\text{mA}$		0.27	0.4	Volts
			$I_{OL} = 8.0\text{mA}$		0.32	0.45	
			$I_{OL} = 12\text{mA}$		0.37	0.5	
V_{IH}	Input HIGH Level (Except Bus)	Guaranteed input logical HIGH for all inputs		2.0			Volts
V_{IL}	Input LOW Level (Except Bus)	Guaranteed input logical LOW for all inputs	MIL			0.7	Volts
			COM'L				
V_I	Input Clamp Voltage (Except Bus)	$V_{CC} = \text{MIN.}$, $I_{IN} = -18\text{mA}$				-1.2	Volts
I_{IL}	Input LOW Current (Except Bus)	$V_{CC} = \text{MAX.}$, $V_{IN} = 0.4\text{V}$	\overline{BE} , RLE			-0.72	mA
			All other inputs				
I_{IH}	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}$, $V_{IN} = 2.7\text{V}$				20	μA
I_I	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}$, $V_{IN} = 7.0\text{V}$				100	μA
I_{SC}	Output Short Circuit Current (Except Bus)	$V_{CC} = \text{MAX.}$	RECEIVER	-30		-130	mA
			PARITY	-20		-100	
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$, All Inputs = GND			75	110	mA

SWITCHING CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions	Am2916AXM			Am2916AXC			Units
			Min.	Typ. (Note 2)	Max.	Min.	Typ. (Note 2)	Max.	
t_{PHL}	Driver Clock (DRCP) to Bus	$C_L (\text{BUS}) = 50\text{pF}$ $R_L (\text{BUS}) = 130\Omega$		21	36		21	32	ns
t_{PLH}				21	36		21	32	
t_{ZH} , t_{ZL}	Bus Enable (\overline{BE}) to Bus			13	26		13	23	ns
t_{HZ} , t_{LZ}				13	21		13	18	
t_s	Data Inputs (A or B)			15		12		ns	
t_h				8.0		6.0			
t_s	Select Inputs (S)			28		25		ns	
t_h				8.0		6.0			
t_{PW}	Clock Pulse Width (HIGH)				20		17	ns	
t_{PLH}	Bus to Receiver Output (Latch Enabled)			18	33		18	30	ns
t_{PHL}				18	30		18	27	
t_{PLH}	Latch Enable to Receiver Output			21	33		21	30	ns
t_{PHL}				21	30		21	27	
t_s	Bus to Latch Enable (\overline{RLE})	$C_L = 15\text{pF}$ $R_L = 2.0\text{k}\Omega$		15		13		ns	
t_h				6.0		4.0			
t_{PLH}	A or B Data to Odd Parity Output (Driver Enabled)			32	46		32	42	ns
t_{PHL}				26	40		26	36	
t_{PLH}	Bus to Odd Parity Output (Driver Inhibited, Latch Enabled)			21	36		21	32	ns
t_{PHL}				21	36		21	32	
t_{PLH}	Latch Enable (\overline{RLE}) to Odd Parity Output			21	36		21	32	ns
t_{PHL}				21	36		21	32	

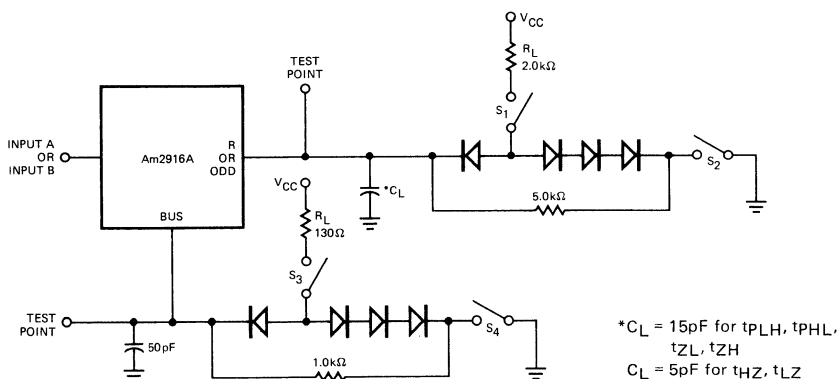
- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

INPUT/OUTPUT CURRENT INTERFACE CONDITIONS

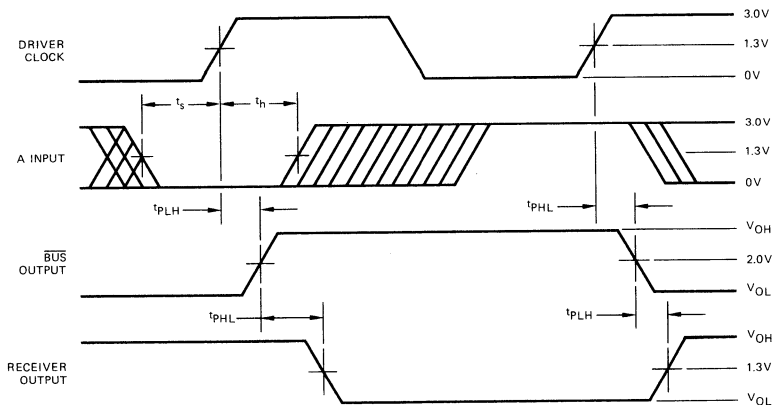


Note: Actual current flow direction shown.

SWITCHING TEST CIRCUIT



SWITCHING WAVEFORMS



Note: Bus to Receiver output delay is measured by clocking data into the driver register and measuring the BUS to R combinatorial delay.

FUNCTION TABLE

INPUTS							INTERNAL TO DEVICE		BUS	OUTPUT	FUNCTION
S	A _i	B _i	DRCP	\overline{BE}	RLE	\overline{OE}	D _i	Q _i	\overline{BUS}_i	R _i	
X	X	X	X	H	X	X	X	X	Z	X	Driver output disable
X	X	X	X	X	X	H	X	X	X	Z	Receiver output disable
X	X	X	X	H	L	L	X	L	L	H	Driver output disable and receive data via Bus input
X	X	X	X	H	L	L	X	H	H	L	Driver output disable and receive data via Bus input
X	X	X	X	X	H	X	X	NC	X	X	Latch received data
L	L	X	↑	X	X	X	L	X	X	X	Load driver register
L	H	X	↑	X	X	X	H	X	X	X	
H	X	L	↑	X	X	X	L	X	X	X	
H	X	H	↑	X	X	X	H	X	X	X	
X	X	X	L	X	X	X	NC	X	X	X	No driver clock restrictions
X	X	X	H	X	X	X	NC	X	X	X	
X	X	X	X	L	X	X	L	X	H	X	Drive Bus
X	X	X	X	L	X	X	H	X	L	X	

H = HIGH
L = LOW

Z = HIGH Impedance
NC = No change

X = Don't care
↑ = LOW-to-HIGH transition

i = 0, 1, 2, 3

DEFINITION OF FUNCTIONAL TERMS

A₀, A₁, A₂, A₃ The "A" word data input into the two input multiplexer of the driver register.

B₀, B₁, B₂, B₃ The "B" word data input into the two input multiplexers of the driver register.

S Select. When the select input is LOW, the A data word is applied to the driver register. When the select input is HIGH, the B word is applied to the driver register.

DRCP Driver Clock Pulse. Clock pulse for the driver register.

\overline{BE} Bus Enable. When the Bus Enable is HIGH, the four drivers are in the high impedance state.

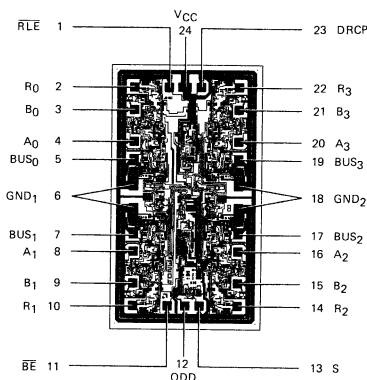
$\overline{BUS}_0, \overline{BUS}_1, \overline{BUS}_2, \overline{BUS}_3$ The four driver outputs and receiver inputs (data is inverted).

R₀, R₁, R₂, R₃ The four receiver outputs. Data from the bus is inverted while data from the A or B inputs is non-inverted.

RLE Receiver Latch Enable. When RLE is LOW, data on the BUS inputs is passed through the receiver latches. When RLE is HIGH, the receiver latches are closed and will retain the data independent of all other inputs.

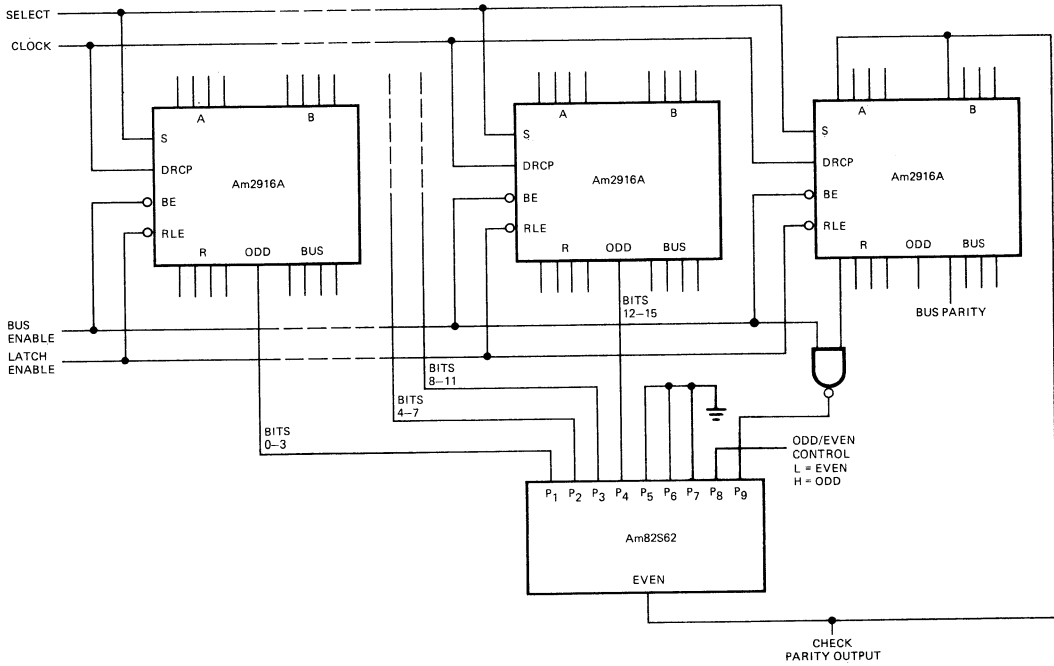
\overline{OE} Output Enable. When the \overline{OE} input is HIGH, the four three state receiver outputs are in the high-impedance state.

Metallization and Pad Layout



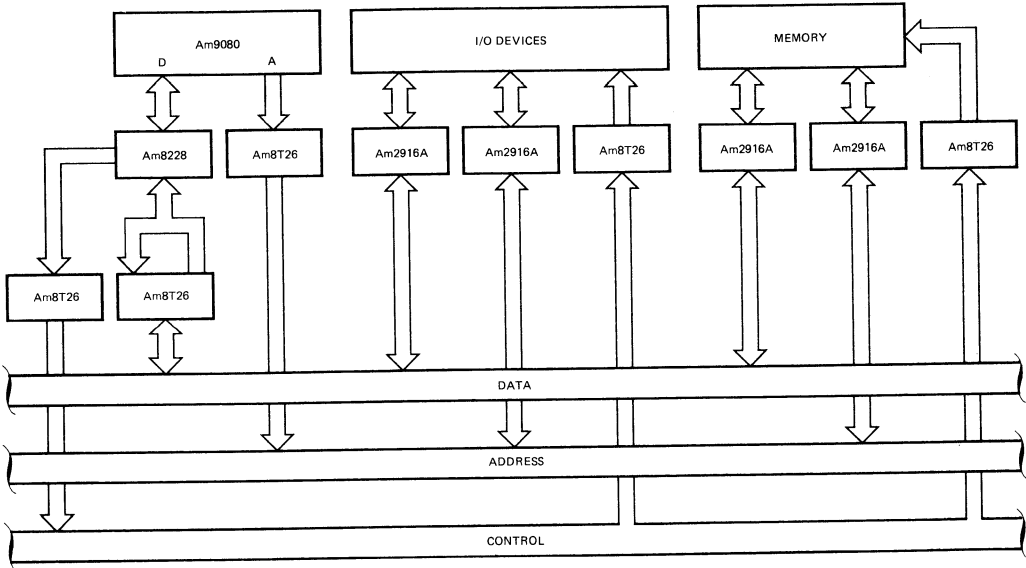
DIE SIZE .074" X .130"

APPLICATIONS



Generating or checking parity for 16 data bits.

3



Using the Am2916A and Am8T26 in a terminated Bus system for the Am9080 MOS Microprocessor.

Am2917A

Quad Three-State Bus Transceiver With Interface Logic

Distinctive Characteristics

- Quad high-speed LSI bus-transceiver
- Three-state bus driver
- D-type register on driver
- Bus driver output can sink 48mA at 0.5V max.
- Internal odd 4-bit parity checker/generator
- Receiver has output latch for pipeline operation
- Three-state receiver outputs sink 12mA
- Advanced low-power Schottky processing
- 100% reliability assurance testing in compliance with MIL-STD-883
- 3.5V minimum output high voltage for direct interface to MOS microprocessors

FUNCTIONAL DESCRIPTION

The Am2917A is a high-performance, low-power Schottky bus transceiver intended for bipolar or MOS microprocessor system applications. The device consists of four D-type edge-triggered flip-flops. The flip-flop outputs are connected to four three-state bus drivers. Each bus driver is internally connected to the input of a receiver. The four receiver outputs drive four D-type latches, that feature three-state outputs. The device also contains a four-bit odd parity checker/generator.

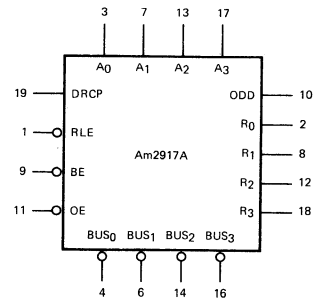
The LSI bus transceiver is fabricated using advanced low-power Schottky processing. All inputs (except the BUS inputs) are one LS unit load. The three-state bus output can sink up to 48mA at 0.5V maximum. The bus enable input (\overline{BE}) is used to force the driver outputs to the high-impedance state. When \overline{BE} is HIGH, the driver is disabled.

The input register consists of four D-type flip-flops with a buffered common clock. The buffered common clock (DRCP) enters the A_i data into this driver register on the LOW-to-HIGH transition.

Data from the A input is inverted at the BUS output. Likewise, data at the BUS input is inverted at the receiver output. Thus, data is non-inverted from driver input to receiver output. The four receivers each feature a built-in D-type latch that is controlled from the buffered receiver latch enable (\overline{RLE}) input. When the \overline{RLE} input is LOW, the latch is open and the receiver outputs will follow the bus inputs (BUS data inverted and \overline{OE} LOW). When the \overline{RLE} input is HIGH, the latch will close and retain the present data regardless of the bus input. The four latches have three-state outputs and are controlled by a buffered common three-state control (\overline{OE}) input. When \overline{OE} is HIGH, the receiver outputs are in the high-impedance state.

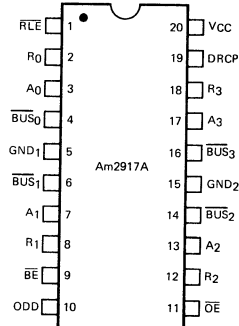
The Am2917A features a built-in four-bit odd parity checker/generator. The bus enable input (\overline{BE}) controls whether the parity output is in the generate or check mode. When the bus enable is LOW (driver enabled), odd parity is generated based on the A field data input to the driver register. When \overline{BE} is HIGH, the parity output is determined by the four latch outputs of the receiver. Thus, if the driver is enabled, parity is generated and if the driver is in the high-impedance state, the BUS parity is checked.

LOGIC SYMBOL



V_{CC} = Pin 20
 GND_1 = Pin 5
 GND_2 = Pin 15

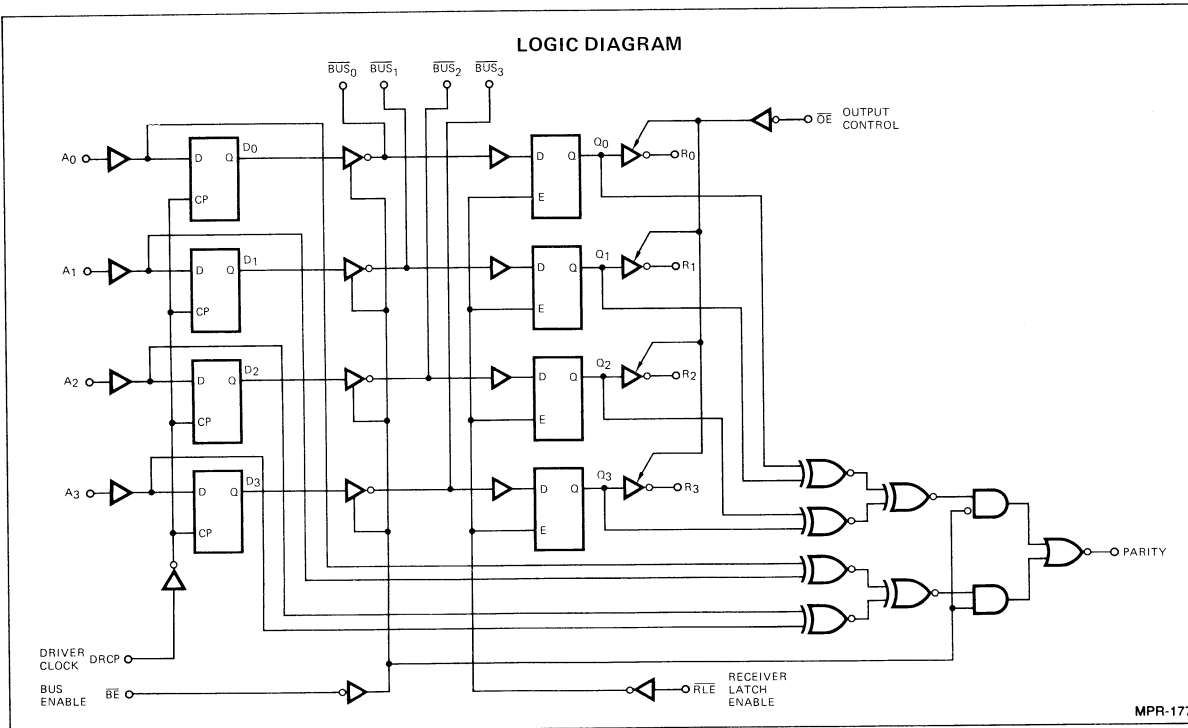
CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM2917APC
Hermetic DIP	0°C to +70°C	AM2917ADC
Dice	0°C to +70°C	AM2917AXC
Hermetic DIP	-55°C to +125°C	AM2917ADM
Hermetic Flat Pak	-55°C to +125°C	AM2917AFM
Dice	-55°C to +125°C	AM2917AXM



MPR-177

3

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential	-0.5 V to +7 V
DC Voltage Applied to Outputs for HIGH Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +7 V
DC Output Current, Into Outputs (Except BUS)	30 mA
DC Output Current, Into Bus	100 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2917AXC (COM'L)	T _A = 0°C to +70°C	V _{CC} MIN. = 4.75 V	V _{CC} MAX. = 5.25 V
Am2917AXM (MIL)	T _A = -55°C to +125°C	V _{CC} MIN. = 4.50 V	V _{CC} MAX. = 5.50 V

BUS INPUT/OUTPUT CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions (Note 1)	Min.	Typ.	Max.	Units
V _{OL}	Bus Output LOW Voltage	V _{CC} = MIN.	I _{OL} = 24 mA		0.4	Volts
			I _{OL} = 48 mA		0.5	
V _{OH}	Bus Output HIGH Voltage	V _{CC} = MIN.	COM'L, I _{OH} = -20 mA	2.4		Volts
			MIL, I _{OH} = -15 mA			
I _O	Bus Leakage Current (High Impedance)	V _{CC} = MAX. Bus enable = 2.4 V	V _O = 0.4 V		-200	μA
			V _O = 2.4 V		50	
			V _O = 4.5 V		100	
I _{OFF}	Bus Leakage Current (Power OFF)	V _O = 4.5 V V _{CC} = 0 V			100	μA
V _{IH}	Receiver Input HIGH Threshold	Bus enable = 2.4 V	2.0			Volts
V _{IL}	Receiver Input LOW Threshold	Bus enable = 2.4 V	COM'L		0.8	Volts
			MIL		0.7	
I _{SC}	Bus Output Short Circuit Current	V _{CC} = MAX. V _O = 0 V	-50	-120	-225	mA

Am2917A

ELECTRICAL CHARACTERISTICS

The following conditions apply unless otherwise noted:

Am2917AXC (COM'L) $T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC\text{ MIN.}} = 4.75\text{ V}$ $V_{CC\text{ MAX.}} = 5.25\text{ V}$

Am2917AXM (MIL) $T_A = -55^\circ\text{C to } +125^\circ\text{C}$ $V_{CC\text{ MIN.}} = 4.50\text{ V}$ $V_{CC\text{ MAX.}} = 5.50\text{ V}$

DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

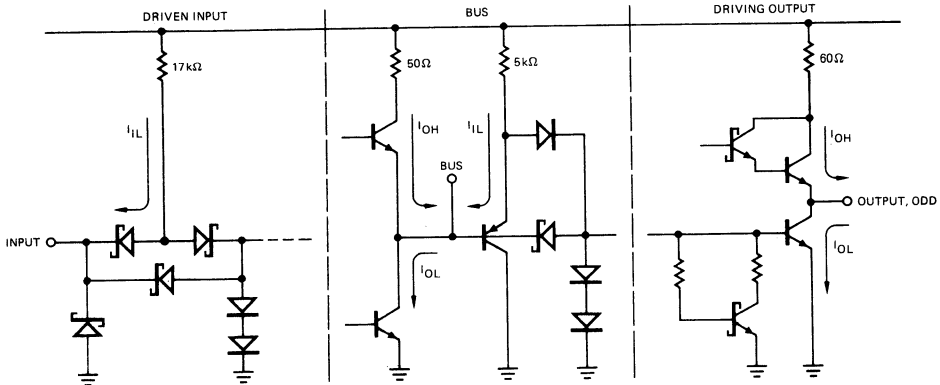
Parameters	Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Receiver Output HIGH Voltage	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IL} \text{ or } V_{IH}$	MIL: $I_{OH} = -1.0\text{ mA}$	2.4	3.4		Volts
			COM'L: $I_{OH} = -2.6\text{ mA}$	2.4	3.4		
		$V_{CC} = 5.0\text{ V}, I_{OH} = -100\mu\text{ A}$	3.5				
V_{OH}	Parity Output HIGH Voltage	$V_{CC} = \text{MIN.}, I_{OH} = -660\mu\text{ A}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL	2.5	3.4		Volts
			COM'L	2.7	3.4		
V_{OL}	Output LOW Voltage (Except Bus)	$V_{CC} = \text{MIN.}$ $V_{IN} = V_{IL} \text{ or } V_{IH}$	$I_{OL} = 4.0\text{ mA}$		0.27	0.4	Volts
			$I_{OL} = 8.0\text{ mA}$		0.32	0.45	
			$I_{OL} = 12\text{ mA}$		0.37	0.5	
V_{IH}	Input HIGH Level (Except Bus)	Guaranteed input logical HIGH for all inputs		2.0			Volts
V_{IL}	Input LOW Level (Except Bus)	Guaranteed input logical LOW for all inputs		MIL		0.7	Volts
				COM'L		0.8	
V_I	Input Clamp Voltage (Except Bus)	$V_{CC} = \text{MIN.}, I_{IN} = -18\text{ mA}$				-1.2	Volts
I_{IL}	Input LOW Current (Except Bus)	$V_{CC} = \text{MAX.}, V_{IN} = 0.4\text{ V}$	$\overline{BE}, \overline{RLE}$			-0.72	mA
			All other inputs			-0.36	
I_{IH}	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}, V_{IN} = 2.7\text{ V}$				20	$\mu\text{ A}$
I_I	Input HIGH Current (Except Bus)	$V_{CC} = \text{MAX.}, V_{IN} = 7.0\text{ V}$				100	$\mu\text{ A}$
I_{SC}	Output Short Circuit Current (Except Bus)	$V_{CC} = \text{MAX.}$	RECEIVER	-30		-130	mA
			PARITY	-20		-100	
I_{CC}	Power Supply Current	$V_{CC} = \text{MAX.}$			63	95	mA
I_O	Off-State Output Current (Receiver Outputs)	$V_{CC} = \text{MAX.}$		$V_O = 2.4\text{ V}$		50	$\mu\text{ A}$
				$V_O = 0.4\text{ V}$		-50	

SWITCHING CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions	Am2917AXM Typ. (Note 2)			Am2917AXC Typ. (Note 2)			Units
			Min.	Max.	Min.	Max.			
t_{PHL}	Driver Clock (DRCP) to Bus	$C_L (\text{BUS}) = 50\text{ pF}$ $R_L (\text{BUS}) = 130\Omega$		21	36		21	32	ns
t_{PLH}				21	36		21	32	
t_{ZH}, t_{ZL}	Bus Enable (\overline{BE}) to Bus			13	26		13	23	ns
t_{HZ}, t_{LZ}				13	21		13	18	
t_s	A Data Inputs			15			12		ns
t_h				8.0			6.0		
t_{PW}				20			17		
t_{PLH}	Bus to Receiver Output (Latch Enabled)			18	33		18	30	ns
t_{PHL}				18	30		18	27	
t_{PLH}	Latch Enable to Receiver Output			21	33		21	30	ns
t_{PHL}				21	30		21	27	
t_s	Bus to Latch Enable (\overline{RLE})	$C_L = 15\text{ pF}$ $R_L = 2.0\text{ k}\Omega$		15			13		ns
t_h				6.0			4.0		
t_{PLH}	A Data to Odd Parity Out (Driver Enabled)			32	46		32	42	ns
t_{PHL}				26	40		26	36	
t_{PLH}	Bus to Odd Parity Out (Driver Inhibit)			21	36		21	32	ns
t_{PHL}				21	36		21	32	
t_{PLH}	Latch Enable (\overline{RLE}) to Odd Parity Output			21	36		21	32	ns
t_{PHL}				21	36		21	32	
t_{ZH}, t_{ZL}	Output Control to Output	$C_L = 5\text{ pF}, R_L = 2.0\text{ k}\Omega$		14	26		14	23	ns
t_{HZ}, t_{LZ}				14	26		14	23	

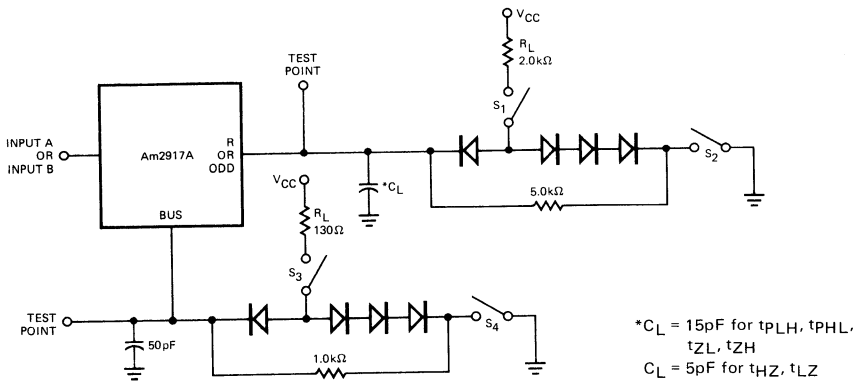
- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at $V_{CC} = 5.0\text{ V}$, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

INPUT/OUTPUT CURRENT INTERFACE CONDITIONS

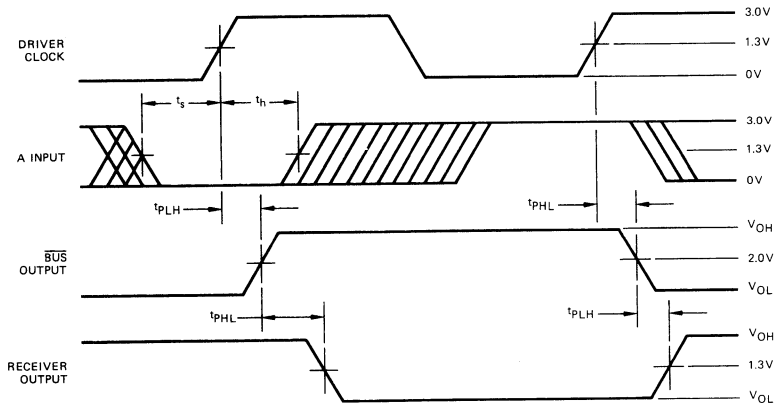


Note: Actual current flow direction shown.

SWITCHING TEST CIRCUIT



SWITCHING WAVEFORMS



Note: Bus to Receiver output delay is measured by clocking data into the driver register and measuring the BUS to R combinatorial delay.

FUNCTION TABLE

INPUTS					INTERNAL TO DEVICE		BUS	OUTPUT	FUNCTION
A _i	DRCP	\overline{BE}	\overline{RLE}	\overline{OE}	D _i	Q _i	BUS _i	R _i	
X	X	H	X	X	X	X	Z	X	Driver output disable
X	X	X	X	H	X	X	X	Z	Receiver output disable
X	X	H	L	L	X	L	L	H	Driver output disable and receive data via Bus input
X	X	H	L	L	X	H	H	L	
X	X	X	H	X	X	NC	X	X	Latch received data
L	↑	X	X	X	L	X	X	X	Load driver register
H	↑	X	X	X	H	X	X	X	
X	L	X	X	X	NC	X	X	X	No driver clock restrictions
X	H	X	X	X	NC	X	X	X	
X	X	L	X	X	L	X	H	X	Drive Bus
X	X	L	X	X	H	X	L	X	

H = HIGH Z = High Impedance X = Don't Care i = 0, 1, 2, 3
 L = LOW NC = No Change ↑ = LOW-to-HIGH Transition

PARITY OUTPUT FUNCTION TABLE

\overline{BE}	ODD PARITY OUTPUT
L	ODD = A ₀ ⊕ A ₁ ⊕ A ₂ ⊕ A ₃
H	ODD = Q ₀ ⊕ Q ₁ ⊕ Q ₂ ⊕ Q ₃

DEFINITION OF FUNCTIONAL TERMS

DRCP Driver Clock Pulse. Clock pulse for the driver register.

\overline{BE} Bus Enable. When the Bus Enable is LOW, the four drivers are in the high impedance state.

BUS₀, BUS₁, BUS₂, BUS₃ The four driver outputs and receiver inputs (data is inverted).

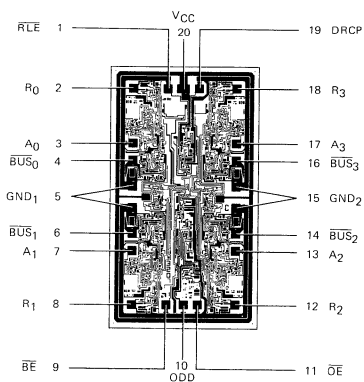
R₀, R₁, R₂, R₃ The four receiver outputs. Data from the bus is inverted while data from the A or B inputs is non-inverted.

\overline{RLE} Receiver Latch Enable. When \overline{RLE} is LOW, data on the BUS inputs is passed through the receiver latches. When \overline{RLE} is HIGH, the receiver latches are closed and will retain the data independent of all other inputs.

ODD Odd parity output. Generates parity with the driver enabled, checks parity with the driver in the high-impedance state.

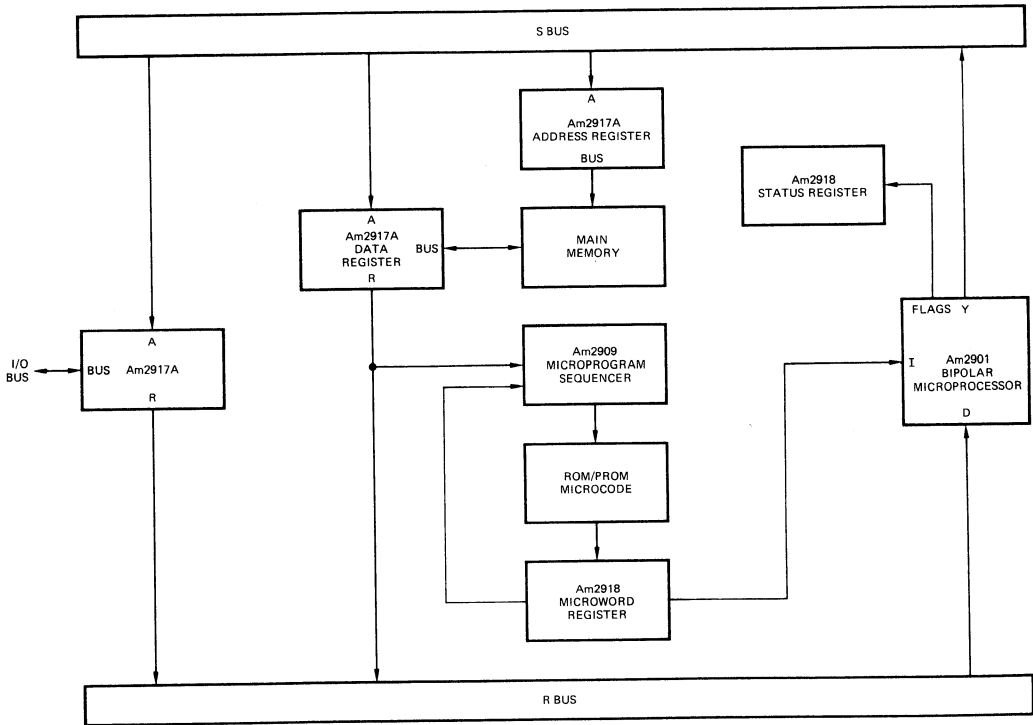
\overline{OE} Output Enable. When the \overline{OE} input is HIGH, the four three-state receiver outputs are in the high-impedance state.

Metallization and Pad Layout

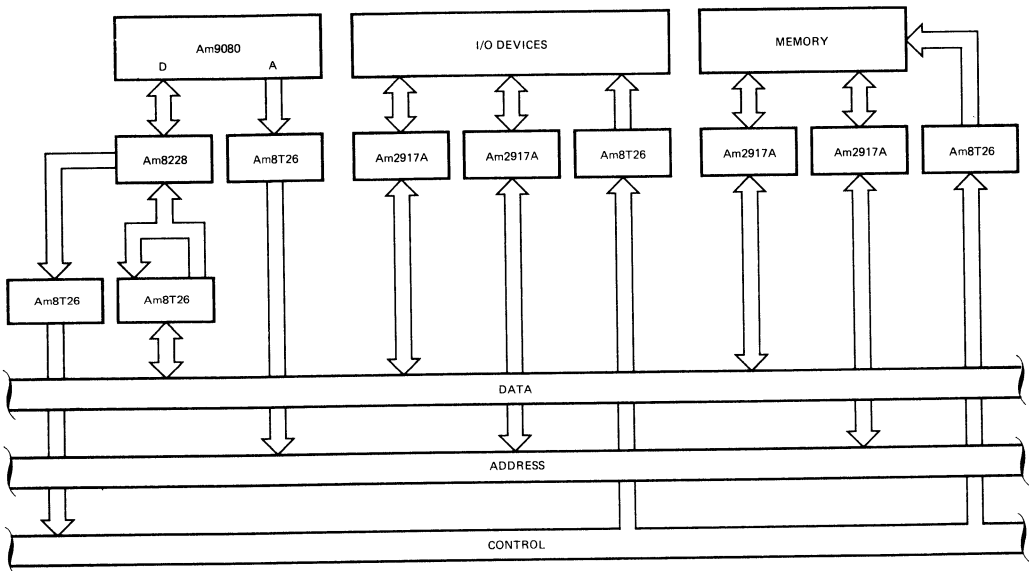


DIE SIZE .074" X .130"

APPLICATIONS



The Am2917A can be used as an I/O Bus Transceiver and Main Memory I/O Transceiver in high-speed Microprocessor Systems.



Using the Am2917A and Am8T26 in a terminated Bus system for the Am9080 MOS Microprocessor.

HIGH SPEED SCHOTTKY S-MSI AND INTERFACE DATA SHEETS

Definition of Standard Schottky Terms	4-2	Am54S/74S350	4-112
Am25S05	4-3	Am54S/74S373/S533	4-114
Am25S07/08	4-9	Am54S/74S374/S534	4-115
Am25S09	4-29	Am54S/74S378/S379	4-118
Am25S10	4-33	Am54S/74S388	4-116
Am25S18	4-47	Am54S/74S399	4-120
Am26S02	4-51	Am54S/74S412	4-122
Am26S10/S11	4-55	Am3212/8212	4-123
Am26S12/S12A	4-60	Am8T26	4-130
Am54S/74S138	4-65	Am8T26A/8T28	4-135
Am54S/74S139/93S21	4-69	Am82S62	4-140
Am54S/74S151/S251	4-73	Am8304	4-144
Am54S/74S153/S253	4-77	Am93S10/S16	4-148
Am54S/74S157/S158/93S22	4-81	Am93S48	4-152
Am54S/74S160/S161	4-85		
Am54S/74S174/S175	4-89		
Am54S/74S181	4-93		
Am54S/74S194/S195	4-99		
Am54S/74S240/S241/S242/S243/S244	4-103		
Am54S/74S257/S258	4-108		

APPLICATION NOTES	
Schottky TTL MSI Registers	4-13
Am25S10 Four-Bit Shifter	4-37

DEFINITION OF A.C. (SWITCHING) TERMS

(All switching times are measured at the 1.5V logic level unless otherwise noted.)

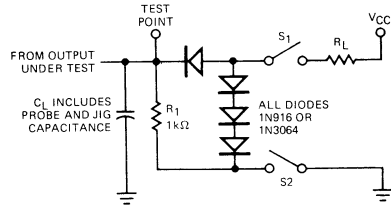
- f_{MAX}** The highest operating clock frequency.
- t_{PLH}** The propagation delay time from an input change to an output LOW-to-HIGH transition.
- t_{PHL}** The propagation delay time from an input change to an output HIGH-to-LOW transition.
- t_{PW}** Pulse width. The time between the leading and trailing edges of a pulse.
- t_r** Rise time. The time required for a signal to change from 10% to 90% of its measured values.
- t_f** Fall time. The time required for a signal to change from 90% to 10% of its measured values.
- t_s** Set-up time. The time interval for which a signal must be applied and maintained at one input terminal before an active transition occurs at another input terminal.
- t_h** Hold time. The time interval for which a signal must be retained at one input after an active transition occurs at another input terminal.
- t_R** Release time. The time interval for which a signal may be indeterminant at one input terminal before an active transition occurs at another input terminal. (The release time falls within the set-up time interval and is specified by some manufacturers as a negative hold time).
- t_{HZ}** HIGH to disable. The delay time from a control input change to the three-state output HIGH-level to high-impedance transition (measured at 0.5 V change).
- t_{LZ}** LOW to disable. The delay time from a control input change to the three-state output LOW-level to high-impedance transition (measured at 0.5 V change).
- t_{ZH}** Enable HIGH. The delay time from a control input change to the three-state output high-impedance to HIGH-level transition.
- t_{ZL}** Enable LOW. The delay time from a control input change to the three-state output high-impedance to LOW-level transition.

DEFINITION OF D.C. TERMS

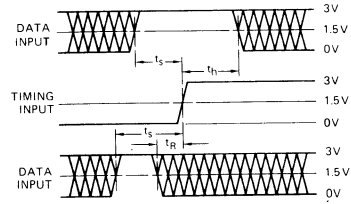
- H** HIGH, applying to a HIGH voltage level.
- L** LOW, applying to a LOW voltage level.
- I** Input.
- O** Output.
- Negative Current** Current flowing out of the device.
- Positive Current** Current flowing into the device.
- I_{IL}** LOW-level input current with a specified LOW-level voltage applied.
- I_{IH}** HIGH-level input current with a specified HIGH-level voltage applied.
- I_{OL}** LOW-level output current.
- I_{OH}** HIGH-level output current.
- I_{SC}** Output short-circuit source current.
- I_{CC}** The supply current drawn by the device from the V_{CC} power supply.
- V_{IL}** Logic LOW input voltage.
- V_{IH}** Logic HIGH input voltage.
- V_{OL}** LOW-level output voltage with I_{OL} applied.
- V_{OH}** HIGH-level output voltage with I_{OH} applied.

SCHOTTKY PARAMETER MEASUREMENTS FOR THREE-STATE OUTPUTS

LOAD TEST CIRCUIT

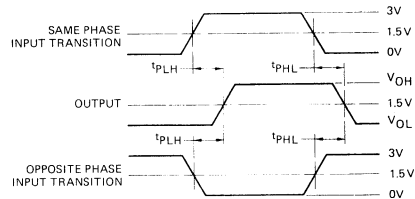


SET-UP, HOLD, AND RELEASE TIMES

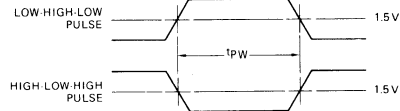


- Notes: 1. Diagram shown for HIGH data only. Output transition may be opposite sense.
- 2. Cross hatched area is don't care condition.

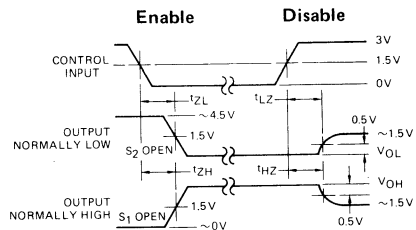
PROPAGATION DELAY



PULSE WIDTH



ENABLE AND DISABLE TIMES



- Notes: 1. Diagram shown for Input Control Enable-LOW and Input Control Disable-HIGH.
- 2. S₁ and S₂ of Load Circuit are closed except where shown.

Note: 1. Pulse Generator for All Pulses: Rate ≤ 1.0MHz; Z_o = 50Ω; t_r ≤ 2.5 ns; t_f ≤ 2.5 ns.

4

Am25S05

Four-Bit by Two-Bit 2's Complement Multiplier

Distinctive Characteristics

- Provides 2's complement multiplication at high speed without correction.
- Can be used in a combinatorial array or in a time sequenced mode.
- Multiplies two 12-bit signed numbers in typically 115ns.
- Multiplies in active HIGH (positive logic) or active LOW (negative logic) representations.
- Reduced input loading as compared to Am2505.
- 100% reliability assurance testing in compliance with MIL-STD-883.

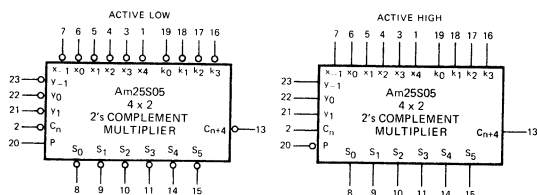
FUNCTIONAL DESCRIPTION

The Am25S05 is a high-speed digital multiplier that can multiply numbers represented in the 2's complement notation and produce a 2's complement product without correction. The device consists of a 4x2 multiplier that can be connected to form iterative arrays able to multiply numbers either directly, or in a time sequenced arrangement. The device assumes that the most significant digit in a word carries a negative weight, and can therefore be used in arrays where the multiplicand and multiplier have different word lengths. The multiplier uses the quaternary algorithm and performs the function $S = XY + K$ where K is the input field used to add partial products generated in the array. At the beginning of the array the inputs are available to add a signed constant to the least significant part of the product. Multiplication of an m bit number by an n bit number in an array results in a product having m+n bits so that all possible combinations of product are accounted for. If a conventional 2's complement product is required the most significant bit can be ignored, and overflow conditions can be detected by comparing the last two product digits.

A number of connection schemes are possible. Figure 1 shows the connection scheme that results in the fastest multiply. If higher speed is required an array can be split into several parts, and the parts added with high-speed look-ahead carry adders.

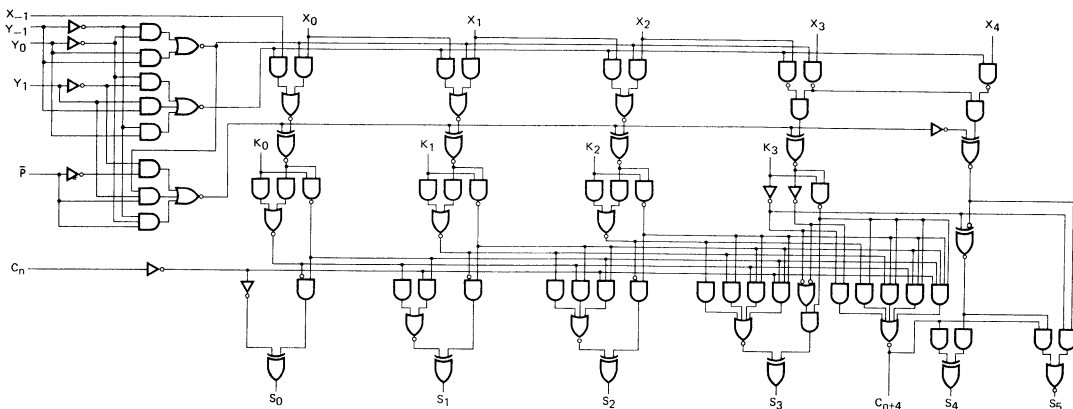
Provision is made in the design for multiplication in the active high (positive logic) or active low (negative logic) representations simply by reinterpreting the active level of the input operands, the product, and a polarity control P.

LOGIC SYMBOLS



VCC = Pin 24
GND = Pin 12

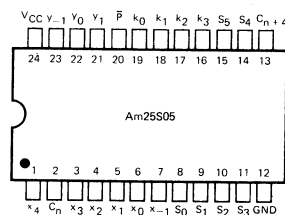
LOGIC DIAGRAM



Am25S05 ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +75°C	AM25S05PC
Hermetic DIP	0°C to +75°C	AM25S05DC
Dice	0°C to +75°C	AM25S05XC
Hermetic DIP	-55°C to +125°C	AM25S05DM
Hermetic Flat Pak	-55°C to +125°C	AM25S05FM
Dice	-55°C to +125°C	AM25S05XM

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 24 to Pin 12) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for High Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5 mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am25S05XC, DC, PC	T _A = 0°C to +75°C	V _{CC} = 4.75 V to 5.25 V
Am25S05XM, DM	T _A = -55°C to +125°C	V _{CC} = 4.50 V to 5.50 V
Am25S05FM	T _C = -55°C to +125°C	V _{CC} = 4.50 V to 5.50 V

Parameters	Description	Test Conditions	Min.	Typ. (Note 1)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1.0mA V _{IN} = V _{IH} or V _{IL}	XM	2.5	3.3		Volts
			XC	2.7	3.3		
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}		0.3	0.5	Volts	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts	
I _{IL} (Note 2)	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V			-2.0	mA	
I _{IH} (Note 2)	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			50	μA	
	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA	
I _{SC}	Output Short Circuit Current	V _{CC} = MAX., V _{OUT} = 0.0V	-40		-100	mA	
I _{CC}	Power Supply Current	V _{CC} = MAX., Y ₁ = 0V		120	175	mA	

Note 1. Typical Limits are at V_{CC} = 5.0V, 25°C Ambient and maximum loading.

Note 2. Actual input currents are obtained by multiplying unit load current by the input load factor. (See loading rules)

Switching Characteristics (V_{CC} = 5 V, T_A = 25°C, C_L = 15 pF, R_L = 280Ω)

Parameters	From (Input)	To (Output)	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH} t _{PHL}	C _n	C _{n+4}	See Test Table	4	8	12	ns
				4	9	14	
t _{PLH} t _{PHL}	C _n	S _{0,1,2,3}		6	12	18	ns
				5	10	15	
t _{PLH} t _{PHL}	C _n	S _{4,5}		7	15	22	ns
				6	13	20	
t _{PLH} t _{PHL}	Any k	C _{n+4}		3	6.5	12	ns
				5	10	15	
t _{PLH} t _{PHL}	Any k	S _{0,1,2,3}		6	13.5	20	ns
				4	9.5	14	
t _{PLH} t _{PHL}	Any k	S _{4,5}		3	15.5	23	ns
				3	12.5	19	
t _{PLH} t _{PHL}	Any x	C _{n+4}		8	17	26	ns
				9	18	27	
t _{PLH} t _{PHL}	Any x	S _{0,1,2,3}		10	21	32	ns
				10	21	32	
t _{PLH} t _{PHL}	Any x	S _{4,5}	6	23.5	35	ns	
			5	21.5	32		
t _{PLH} t _{PHL}	Any y	C _{n+4}	11	23	34	ns	
			10	20	30		
t _{PLH} t _{PHL}	Any y	S _{0,1,2,3}	11	23	34	ns	
			11	23	34		
t _{PLH} t _{PHL}	Any y	S _{4,5}	12	25	37	ns	
			12	25	37		

SWITCHING TIME TEST TABLE

Input	Outputs	Inputs at 0V (remaining inputs at 4.5V)
C_n	$C_{n+4}, S_{0123}, S_{45}$	P, Y_{-1}, Y_1 , All X
k_0	$C_{n+4}, S_{0123}, S_{45}$	P, Y_{-1}, Y_1 , All X
k_1	C_{n+4}, S_{123}, S_{45}	P, Y_{-1}, Y_1 , All X
k_2	C_{n+4}, S_{23}, S_{45}	P, Y_{-1}, Y_1 , All X
k_3	S_3	P, Y_{-1}, Y_1 , All X
k_3	S_{45}	P, Y_{-1}, Y_1 , All X, C_n
x_{-1}	$C_{n+4}, S_{0123}, S_{45}$	P, Y_1 , All k
x_0	$C_{n+4}, S_{0123}, S_{45}$	P, Y_{-1}, Y_1 , All k
x_1	C_{n+4}, S_{123}, S_{45}	P, Y_{-1}, Y_1 , All k
x_2	C_{n+4}, S_{123}, S_{45}	P, Y_{-1}, Y_1 , All k
x_3	S_3	P, Y_{-1}, Y_1 , All k
x_3	S_{45}	P, Y_{-1}, Y_1 , All k, C_n
x_4	S_{45}	P, Y_1 , All k, C_n
Y_{-1}	$C_{n+4}, S_{0123}, S_{45}$	P, X_1, X_2, X_3, X_4 , All k
Y_0	$C_{n+4}, S_{0123}, S_{45}$	P, X_1, X_2, X_3, X_4 , All k
Y_1	$C_{n+4}, S_{0123}, S_{45}$	X_0, X_1, X_2, X_3, X_4 , All k

DEFINITION OF TERMS

SUBSCRIPT TERMS:

H HIGH, applying to a HIGH logic level or when used with V_{CC} to indicate high V_{CC} value.

I Input.

L LOW, applying to LOW logic level or when used with V_{CC} to indicate low V_{CC} value.

O Output.

FUNCTIONAL TERMS

C_n The carry input to the high-speed adder.

C_{n+4} The carry output from the high-speed adder.

k_i The constant field used for accumulating partial products.

$i = 0, 1, 2, 3$. At the beginning of the array the K field can be used to add a 2's complement number to the least significant half of the double length product.

P The polarity control input. This input must be at a low-logic level for numbers in the active high logic representation, and held high for numbers in the active low logic representation.

S_i The product outputs. $i = 0, 1, 2, 3, 4, 5$.

x_i The multiplicand inputs. $i = -1, 0, 1, 2, 3, 4$. At the first column

of the array x_{-1} must be held at logic '0', and at the last column of the array x_4 is connected to x_3 .

y_i The multiplier inputs. $i = -1, 0, 1$.

At the first row of the array y_{-1} must be held at logic '0'.

OPERATIONAL TERMS:

I_{IL} Forward input load current.

I_{OH} Output HIGH current, forced out of output in V_{OH} test.

I_{OL} Output LOW current, forced into the output in V_{OL} test.

I_{CC} The current drawn by the device from V_{CC} power supply with input and output terminals open.

I_{IH} Reverse input load current.

Negative Current Current flowing out of the device.

Positive Current Current flowing into the device.

V_{IH} Minimum logic HIGH input voltage.

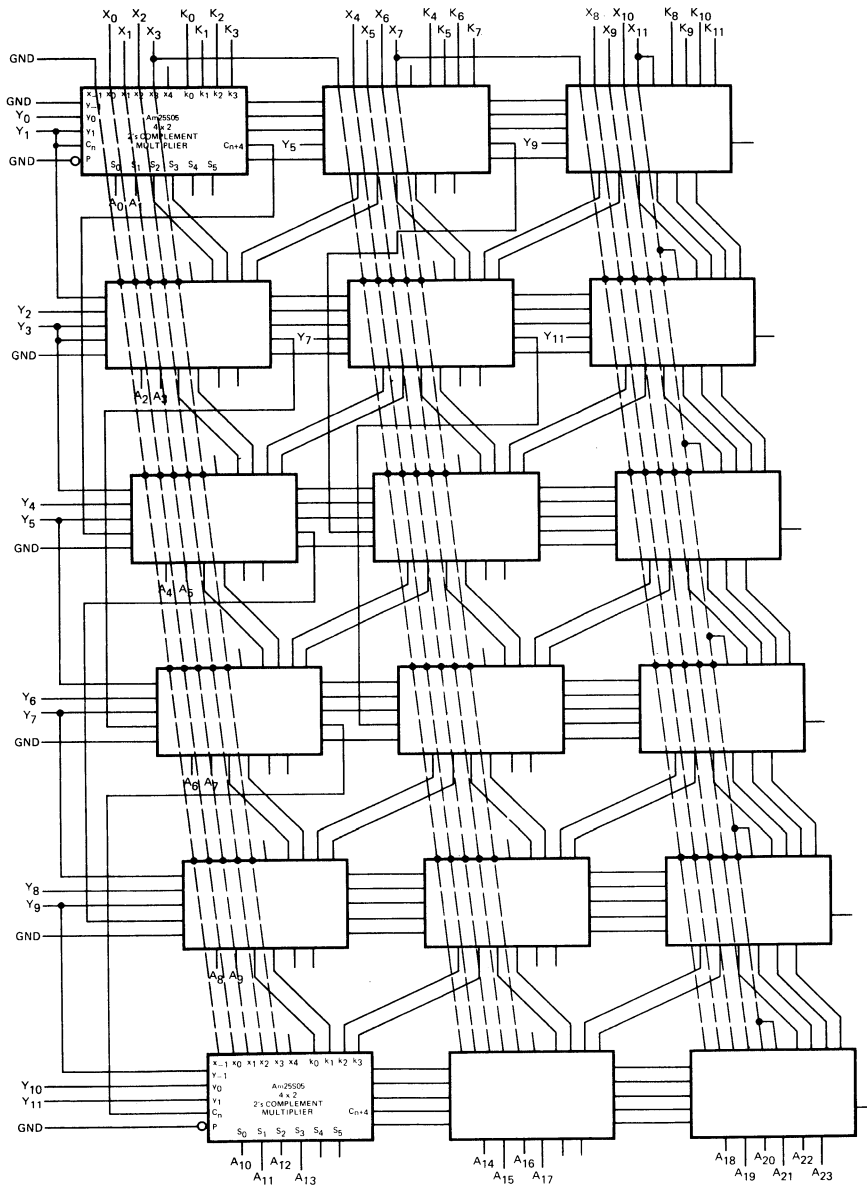
V_{IL} Maximum logic LOW input voltage.

V_{IN} Input voltage applied in I_{IL}, I_{IH} tests.

V_{OH} Minimum logic HIGH output voltage with output HIGH current I_{OH} flowing out of output.

V_{OL} Maximum logic LOW output voltage with output LOW current I_{OL} flowing into output.

APPLICATION



Critical speed carries between columns have been interchanged with 2's complement carry-ins Y_5, Y_7, Y_9, Y_{11} for highest speed.

Figure 1. High Speed 12x12 2's Complement Multiplication

MSI INTERFACING RULES

Interfacing Digital Family	Equivalent Input Unit Load	
	HIGH	LOW
Advanced Micro Devices 54/7400 Series	1.25	1.25
Advanced Micro Devices 9300/2500 Series	1.25	1.25
FSC Series 9300	1.25	1.25
TI Series 54/7400	1.25	1.25
Signetics Series 8200	2.5	2.5
National Series DM 75/85	1.25	1.25
DTL Series 930	15	1.25

OPERATION TABLE

Y Multiplier			Operation X Multiplicand
Y-1	Y ₀	Y ₁	
0	0	0	K + 0
1	0	0	K + X
0	1	0	K + X
1	1	0	K + 2X
0	0	1	K - 2X
1	0	1	K - X
0	1	1	K - X
1	1	1	K - 0

Active Low Inputs and Outputs
 '1' = Low, '0' = High, P = High
 Active High Inputs and Outputs
 '1' = High, '0' = Low, P = Low

Am25S05 LOADING RULES IN UNIT LOADS

Input/Output	Pin No.'s	Input Unit Load		Fanout	
		Input HIGH	Input LOW	Output HIGH	Output LOW
x ₄	1	0.2	0.2	—	—
C _n	2	0.2	0.2	—	—
x ₃	3	0.2	0.2	—	—
x ₂	4	0.4	0.4	—	—
x ₁	5	0.4	0.4	—	—
x ₀	6	0.4	0.4	—	—
x ₋₁	7	0.2	0.2	—	—
S ₀	8	—	—	20	10
S ₁	9	—	—	20	10
S ₂	10	—	—	20	10
S ₃	11	—	—	20	10
GND	12	—	—	—	—
C _{n+4}	13	—	—	20	10
S ₄	14	—	—	20	10
S ₅	15	—	—	20	10
k ₃	16	2	2	—	—
k ₂	17	2	2	—	—
k ₁	18	2	2	—	—
k ₀	19	2	2	—	—
P̄	20	1	1	—	—
y ₁	21	0.6	0.6	—	—
y ₀	22	0.6	0.6	—	—
Y-1	23	0.6	0.6	—	—
V _{CC}	24	—	—	—	—

A Schottky TTL Unit Load is defined as 50µA at 2.7V at the HIGH Logic Level and -2.0mA at 0.5V at the LOW Logic Level.

USER NOTES

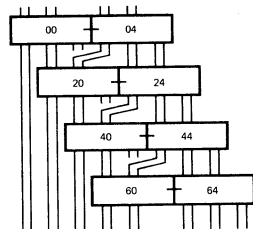
- Arithmetic in the multiplier is performed in the 2's complement notation, which requires a carry in at the first stage. This is accomplished by connecting the y_i multiplier bit to the appropriate carry input terminal i = 1, 3, 5...
- The multiplier can perform multiplication in either the active high (positive logic) or active low (negative logic) representations by reinterpreting the active logic level and by grounding or leaving the polarity control pin P open circuit respectively.
- Multiplication can be performed in number representations other than 2's complement by either correcting the 2's complement product or adding in a correction at the beginning of the multiplication at the K inputs. 2's complement numbers are represented as: $X_2 = x - x_s 2^{n-1}$

Number representation	Correction
2's complement	None
1's complement	Add $x_s Y_2 + y_s X_2 + x_s Y_s$ at k inputs
Unsigned (magnitude)	Extend multiplier and multiplicand one bit at the least significant end. Form $x_0 Y_0 + y_0 X + x_0 Y$ with conditional adder and add to array shifted two places up at k inputs. Force $k_s, Y_s, x_s = 0$.

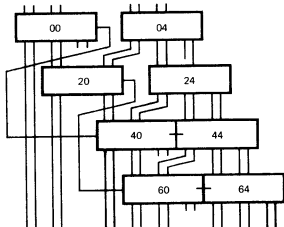
Sign magnitude $x_s = 0, y_s = 0$ None
 $x_s = 1, y_s = 0$ Form $[(XY)_2 + 2^{n-1} y]$
 $x_s = 0, y_s = 1$ Form $[(XY)_2 + 2^{n-1} x]$
 $x_s = 1, y_s = 1$ Add $2^{n-1}(x + y) - 2^{2n-2}$

- For the highest speed array with the multipliers arranged in a parallelogram structure carries between certain multipliers are exchanged with the y carry-ins needed for 2's complement subtract. The delays in the array are then equalized as best possible as shown in Figure 1.
- For higher speed multiplication the array can be split into several parts that can be added together with high-speed adders.
- Rounding off to a single length product can be achieved by adding a '1' to the array at the most significant positive k input of the array, ignoring the most significant product digit, and using the remainder of the most significant part of the product.
- Truncation of a product without round off enables some of the multipliers in the array to be removed.

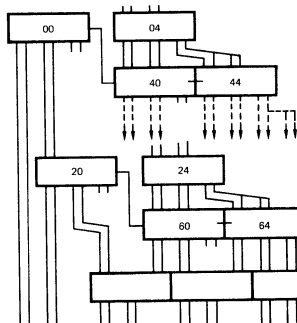
CONNECTION SCHEMES



1
PARALLELOGRAM
CARRIES STAY
IN SAME ROW



2
PARALLELOGRAM
CARRIES FROM
LOWER ORDER
MULTIPLIERS SKIP
TO ALTERNATE ROWS
WHERE POSSIBLE



3
SPLIT INTO
TWO PARTS WHICH
ARE ADDED WITH
HIGH-SPEED
CARRY LOOKAHEAD ADDEP

HIGH-SPEED SCHOTTKY
CARRY LOOKAHEAD ADDER

TYPICAL MULTIPLICATION TIMES

Array Size Bits	Total Multiplication Time (ns)	Package Count	
		Am25S05	Am54S/74S181
4x4	35	2	
8x8	75	8	
12x12	115	18	
12x12	82	18	5
16x16	155	32	
16x16	111	32	7
16x16	98	32	16
20x20	195	50	
20x20	130	50	9
24x24	235	72	
24x24	149	72	11
24x24	125	72	24
28x28	275	98	
28x28	168	98	13
32x32	315	128	
32x32	187	128	15
32x32	152	128	32



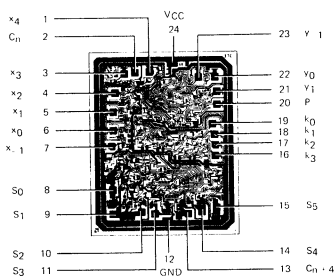
Am25S05

$$Y = (y_{-1} y_0 y_1) 2^A$$

$$X = (x_{-1} x_0 x_1 x_2 x_3) 2^B$$

Fig. 2

Metallization and Pad Layout



DIE SIZE 0.088" X 0.110"

Am25S07·Am25S08

Hex/Quad Parallel D Registers With Register Enable

Distinctive Characteristics

- 4-bit and 6-bit high-speed parallel registers
- Common clock and common enable

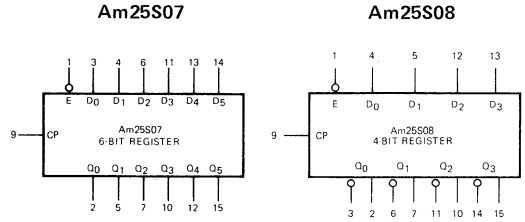
- Positive edge triggered D flip-flops
- 100% reliability assurance testing in compliance with MIL-STD-883.

FUNCTIONAL DESCRIPTION

The Am25S07 is a 6-bit, high-speed Schottky register with a buffered common register enable. The Am25S08 is a 4-bit register with a buffered common register enable. The devices are similar to the Am54S/74S174 and Am54S/74S175 but feature the common register enable rather than common clear.

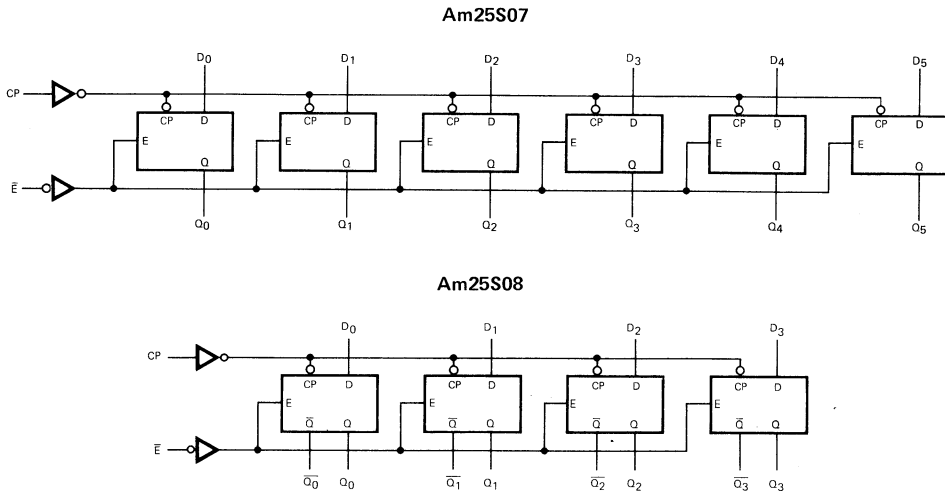
Both registers will find application in digital systems where information is associated with a logic gating signal. When the enable is LOW, data on the D inputs is stored in the register on the positive going edge of the clock pulse. When the enable is HIGH, the register will not change state regardless of the clock or data input transitions.

LOGIC SYMBOLS



V_{CC} = Pin 16
GND = Pin 8

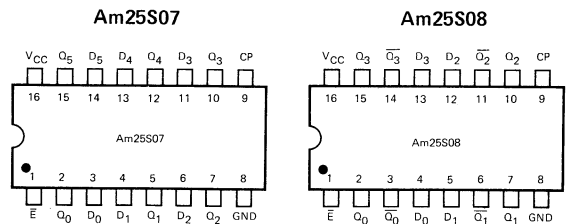
LOGIC DIAGRAMS



ORDERING INFORMATION

Package Type	Temperature Range	Am25S07 Order Number	Am25S08 Order Number
Molded DIP	0°C to +70°C	AM25S07PC	AM25S08PC
Hermetic DIP	0°C to +70°C	AM25S07DC	AM25S08DC
Dice	0°C to +70°C	AM25S07XC	AM25S08XC
Hermetic DIP	-55°C to +125°C	AM25S07DM	AM25S08DM
Hermetic Flat Pak	-55°C to +125°C	AM25S07FM	AM25S08FM
Dice	-55°C to +125°C	AM25S07XM	AM25S08XM

CONNECTION DIAGRAMS Top Views



Note: Pin 1 is marked for orientation.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am25S07XC, Am25S08XC	T _A = 0°C to +70°C	V _{CC} = 5.0V ±5% (COM'L)	MIN. = 4.75V	MAX. = 5.25V
Am25S07XM, Am25S08XM	T _A = -55°C to +125°C	V _{CC} = 5.0V ±10% (MIL)	MIN. = 4.5V	MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1mA V _{IN} = V _{IH} or V _{IL}	XC	2.7	3.4		Volts
			XM	2.5	3.4		
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts	
I _{IL} (Note 3)	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V			-2	mA	
I _{IH} (Note 3)	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			50	μA	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA	
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX.	-40		-100	mA	
I _{CC}	Power Supply Current (Note 5)	V _{CC} = MAX.	S07	90	144	mA	
			S08	60	96		

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
5. Outputs open; enable grounded; data inputs at 4.5V, measured after a momentary ground, then 4.5V applied to the clock input.

4

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{pLH}	Clock to Output	V _{CC} = 5.0V, C _L = 15 pF, R _L = 280Ω	4	8	12	ns
t _{pHL}	Clock to Output		4	11.5	17	ns
t _{pw}	Clock Pulse Width		7			ns
t _s	Data		5.5			ns
t _s	Enable		9			ns
t _h	Data		3			ns
t _h	Enable		3			ns

Am25S07 LOADING RULES
(In STTL Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
\bar{E}	1	1	—	—
Q_0	2	—	20	10
D_0	3	1	—	—
D_1	4	1	—	—
Q_1	5	—	20	10
D_2	6	1	—	—
Q_2	7	—	20	10
GND	8	—	—	—
CP	9	1	—	—
Q_3	10	—	20	10
D_3	11	1	—	—
Q_4	12	—	20	10
D_4	13	1	—	—
D_5	14	1	—	—
Q_5	15	—	20	10
VCC	16	—	—	—

A Schottky TTL Unit Load is defined as 50 μ A measured at 2.7V HIGH and -2.0mA measured at 0.5V LOW.

Am25S08 LOADING RULES
(In STTL Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
\bar{E}	1	1	—	—
Q_0	2	—	20	10
\bar{Q}_0	3	—	20	10
D_0	4	1	—	—
D_1	5	1	—	—
\bar{Q}_1	6	—	20	10
Q_1	7	—	20	10
GND	8	—	—	—
CP	9	1	—	—
Q_2	10	—	20	10
\bar{Q}_2	11	—	20	10
D_2	12	1	—	—
D_3	13	1	—	—
\bar{Q}_3	14	—	20	10
Q_3	15	—	20	10
VCC	16	—	—	—

DEFINITION OF FUNCTIONAL TERMS

D_i The D flip-flop data inputs.

\bar{E} Enable. When the enable is LOW, data on the D_i inputs is transferred to the Q_i outputs on the LOW-to-HIGH clock transition. When the enable is HIGH, the Q_i outputs do not change regardless of the data or clock input transitions.

CP Clock Pulse for the register. Enters data on the LOW-to-HIGH transition.

Q_i The TRUE register outputs.

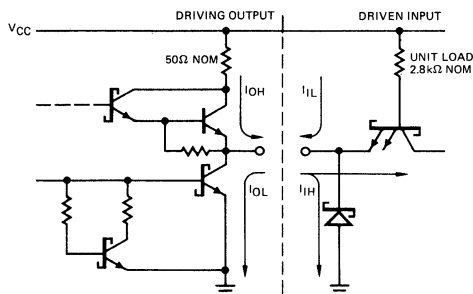
\bar{Q}_i The complement register outputs

FUNCTION TABLE

Inputs			Outputs	
\bar{E}	D_i	CP	Q_i	\bar{Q}_i
H	X	X	NC	NC
L	X	H	NC	NC
L	X	L	NC	NC
L	L	↑	L	H
L	H	↑	H	L

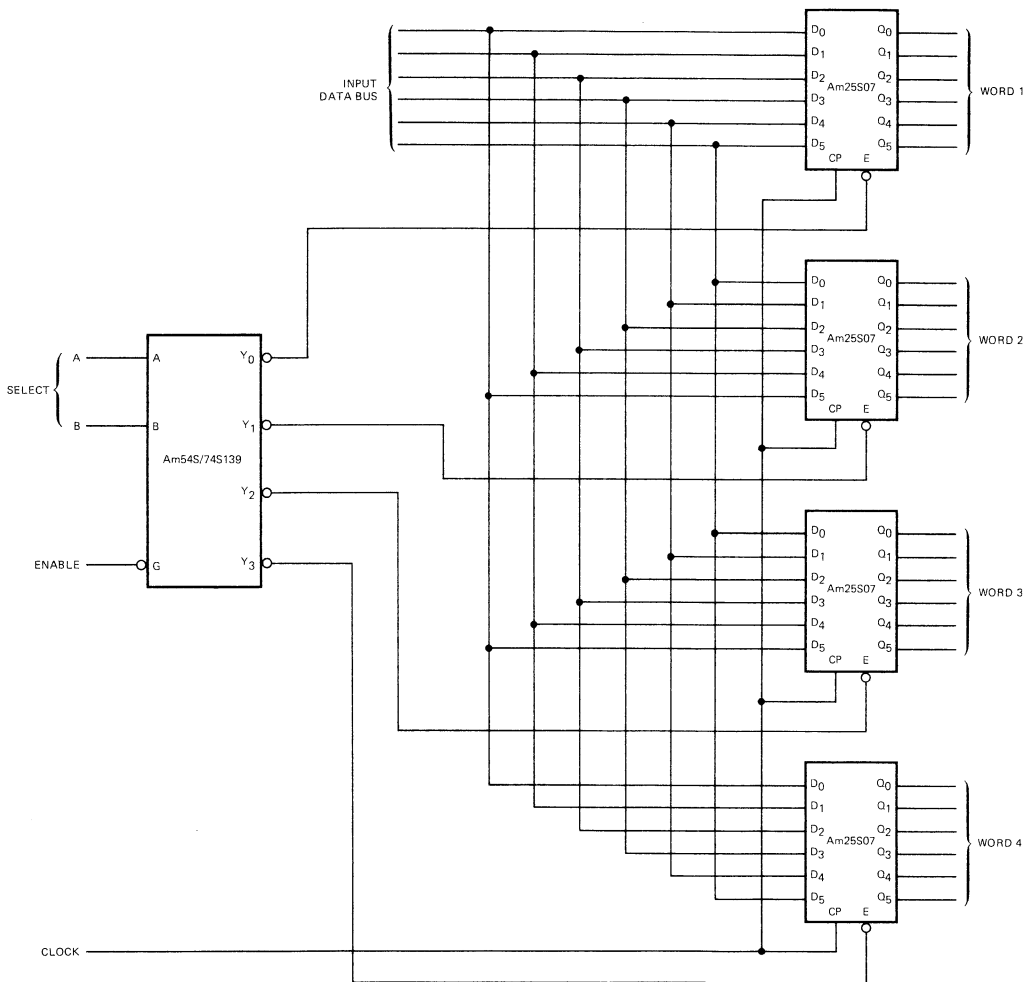
H = HIGH NC = No Change
 L = LOW X = Don't Care
 ↑ = LOW-to-HIGH Transition
 \bar{Q}_i on Am25S08 Only

SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

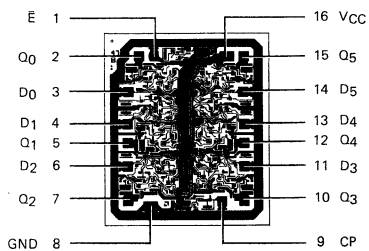
APPLICATIONS



Selective Register Loading of Data on Synchronous Clock.

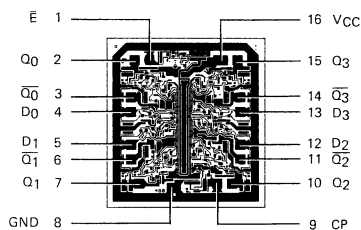
Metallization and Pad Layout

Am25S07



DIE SIZE: 0.070" X 0.083"

Am25S08



DIE SIZE: 0.067" X 0.073"

4

SCHOTTKY TTL MSI REGISTERS

By John R. Mick

INTRODUCTION

There is a continual emphasis on higher and higher speed digital systems. Many TTL MSI functional blocks are now standard items and most high speed digital systems use large numbers of these devices for storage and control. With the advent of Schottky technology, the most popular of these functional storage and control blocks are now available at still higher speeds. In addition, several new, very useful variations of these products are available so that the digital systems designer now has a comprehensive set of register functions available for today's high speed designs.

THE Am54S/74S194 AND Am54S/74S195 SHIFT REGISTERS

The logic diagrams of these advanced Schottky registers together with the logic symbol representing their logic function

are shown in Figure 1. These devices are perhaps the most popular four bit shift registers and are useful for a variety of storage and control functions.

For both registers, the outputs change state synchronously following a LOW-to-HIGH transition on the clock input, CP. Both devices have an active-LOW synchronous clear (CLR) which forces all outputs to the LOW state (\bar{Q}_D HIGH) independent of any other inputs. All control inputs are buffered to present only one Schottky TTL load to the system, and all outputs can drive 10 Schottky loads in the LOW state and 20 in the HIGH state. Because all the flip-flops are D-type, they do not catch 0's or 1's, and the only requirements on any of the inputs is that they meet the short set-up and hold time intervals with respect to the clock LOW-to-HIGH transition.

The Am54S/74S194 shift register operates in four modes under control of the two select inputs, S_0 and S_1 . The four

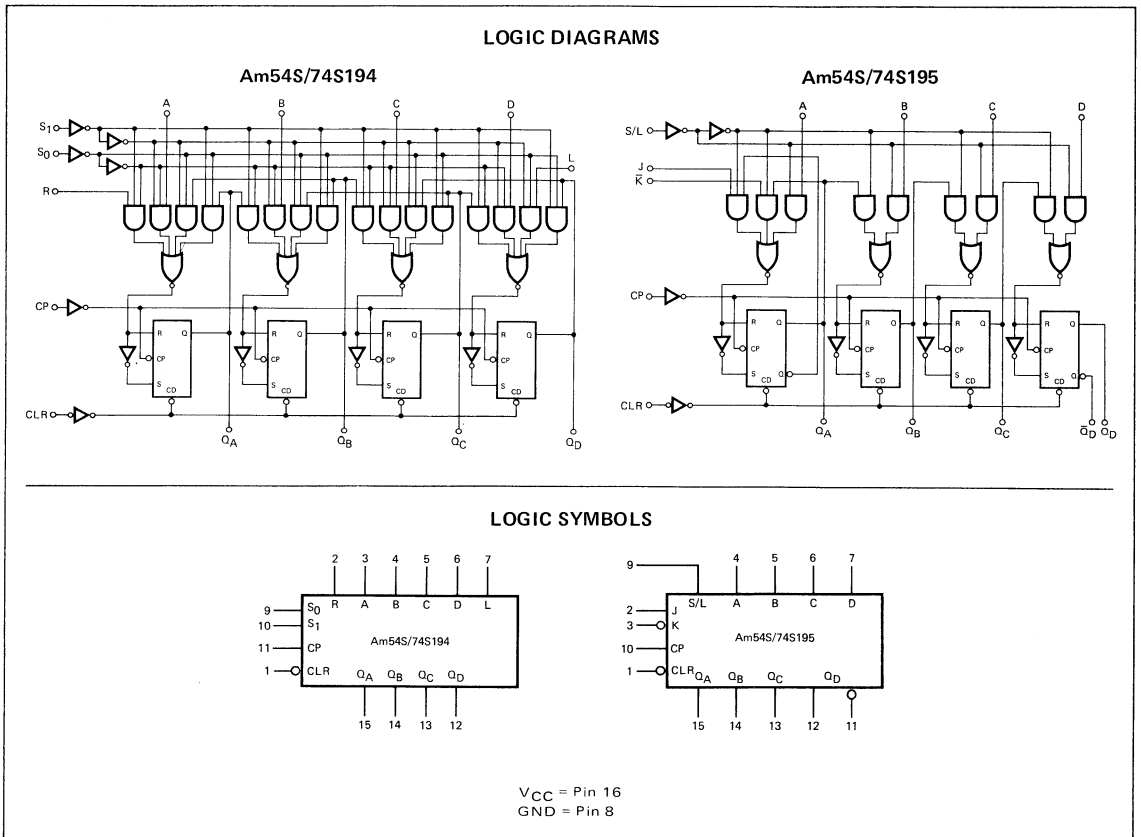


Figure 1. Logic Diagrams and Logic Symbols for the Am54S/74S194 and Am54S/74S195 Shift Registers.

modes are parallel load (data comes from the parallel inputs), shift right (data comes from the flip-flop to the left, with the Q_A bit input from R), shift left (data comes from the flip-flop to the right, with the Q_D input from L), and hold or do nothing (each flip-flop receives data from its own output). It should be noted that on the Am54S/74S194 register there are *no restrictions* on the S_0 and S_1 select inputs when the clock is LOW as there are on the Am54/74194 shift register.

The Am54S/74S195 can either parallel load all four register bits via the parallel inputs (A, B, C, D) or shift each of the four register bits right one place. The shifting or parallel loading is under control of the shift/load input (S/L). When the shift/load input is LOW, data is loaded from the parallel data inputs; when the shift/load input is HIGH, data is loaded from the register bits on the left. The first bit, Q_A , is loaded via the J and \bar{K} inputs in the shift mode. The Function Tables for the Am54S/74S194 and Am54S/74S195 registers are shown in Figure 2.

THE Am25S07 AND Am54S/74S174 SIX-BIT REGISTERS

The logic diagrams and logic symbols representing these 6-bit registers are shown in Figure 3. Both devices consist of six D-type positive edge triggered flip-flops with a buffered common clock. Each flip-flop has a separate D input and a separate Q output.

The Am54S/74S174 register has an asynchronous active-LOW buffered clear input. When the clear input is LOW, the Q outputs are LOW independent of the clock or D inputs.

The Am25S07 is similar to the Am54S/74S174 except the common clear input is replaced by a common active-LOW

clock enable (\bar{E}). When the clock enable input is LOW, the data on the D inputs are stored in the register on the positive going edge of the clock. When the clock enable is HIGH, the register will not change state regardless of the clock or data input transitions.

This clock enable (or strobe) is extremely useful in many applications since it removes the necessity of gating the clock line of the register. Thus, the register can be controlled to enter data as required without additional clock propagation delay. There are no restrictions on this clock enable. The only requirement is that the clock enable input and data inputs meet the set-up and hold times with respect to the clock LOW-to-HIGH transition. The Function Tables for the Am54S/74S174 and Am25S07 registers are shown in Figure 4.

THE Am25S08 AND Am54S/74S175 FOUR-BIT REGISTERS

The logic diagrams for these four-bit registers and the logic symbols representing them are shown in Figure 5. Both devices consist of four D-type positive edge triggered flip-flops with a buffered common clock. Each flip-flop has a separate D input and separate Q and \bar{Q} outputs. Having both outputs available makes these registers particularly useful for general purpose decoding and control applications.

These devices are similar to the Am25S07 and Am54S/74S174 registers in that the Am25S08 has a buffered clock enable input and the Am54S/74S175 has an asynchronous active-LOW buffered clear input. The operation is similar to that described in the previous section and the Function Tables are as shown in Figure 4.

FUNCTION TABLES

Am54S/74S194

FUNCTION	INPUTS								OUTPUTS					
	Clear	Mode		Serial		Parallel				Q_A	Q_B	Q_C	Q_D	
		S_1	S_0	Left	Right	A	B	C	D					
Clear	L	X	X	X	X	X	X	X	X	L	L	L	L	
No Change	H	X	X	L	X	X	X	X	X	NC	NC	NC	NC	
	H	X	X	H	X	X	X	X	X	NC	NC	NC	NC	
Parallel Load	H	H	H	↑	X	X	D_0	D_1	D_2	D_3	D_0	D_1	D_2	D_3
Shift Right	H	L	H	↑	X	L	X	X	X	X	L	Q_A	Q_B	Q_C
	H	L	H	↑	X	H	X	X	X	X	H	Q_A	Q_B	Q_C
Shift Left	H	H	L	↑	L	X	X	X	X	X	Q_B	Q_C	Q_D	L
	H	H	L	↑	H	X	X	X	X	X	Q_B	Q_C	Q_D	H
Hold	H	L	L	X	X	X	X	X	X	X	NC	NC	NC	NC

Am54S/74S195

FUNCTION	INPUTS								OUTPUTS					
	Clear	Shift/Load	Clock	Serial		Parallel				Q_A	Q_B	Q_C	Q_D	\bar{Q}_D
				J	\bar{K}	A	B	C	D					
Clear	L	X	X	X	X	X	X	X	X	L	L	L	L	H
No Change	H	X	L	X	X	X	X	X	X	NC	NC	NC	NC	NC
	H	X	H	X	X	X	X	X	X	NC	NC	NC	NC	NC
Parallel Load	H	L	↑	X	X	D_0	D_1	D_2	D_3	D_0	D_1	D_2	D_3	\bar{D}_3
Shift Right	H	H	↑	L	H	X	X	X	X	Q_A	Q_A	Q_B	Q_C	\bar{Q}_C
	H	H	↑	L	L	X	X	X	X	L	Q_A	Q_B	Q_C	\bar{Q}_C
Shift Left	H	H	↑	H	H	X	X	X	X	H	Q_A	Q_B	Q_C	\bar{Q}_C
	H	H	↑	H	L	X	X	X	X	\bar{Q}_A	Q_A	Q_B	Q_C	\bar{Q}_C

H = HIGH
 L = LOW
 ↑ = LOW-to-HIGH transition.
 D_i = May be a HIGH or a LOW and the respective output will assume the same state.
 X = Don't Care
 NC = No Change

Notes: 1. If the J and \bar{K} inputs are tied together, the common line becomes a D-Type input to the first bit in the shift mode.
 2. Linear feedback shift counters can be made by connecting the Q_D and \bar{Q}_D outputs to the \bar{K} and J inputs, respectively.

Figure 2. Function Tables for the Am54S/74S194 and Am54S/74S195 Shift Registers.

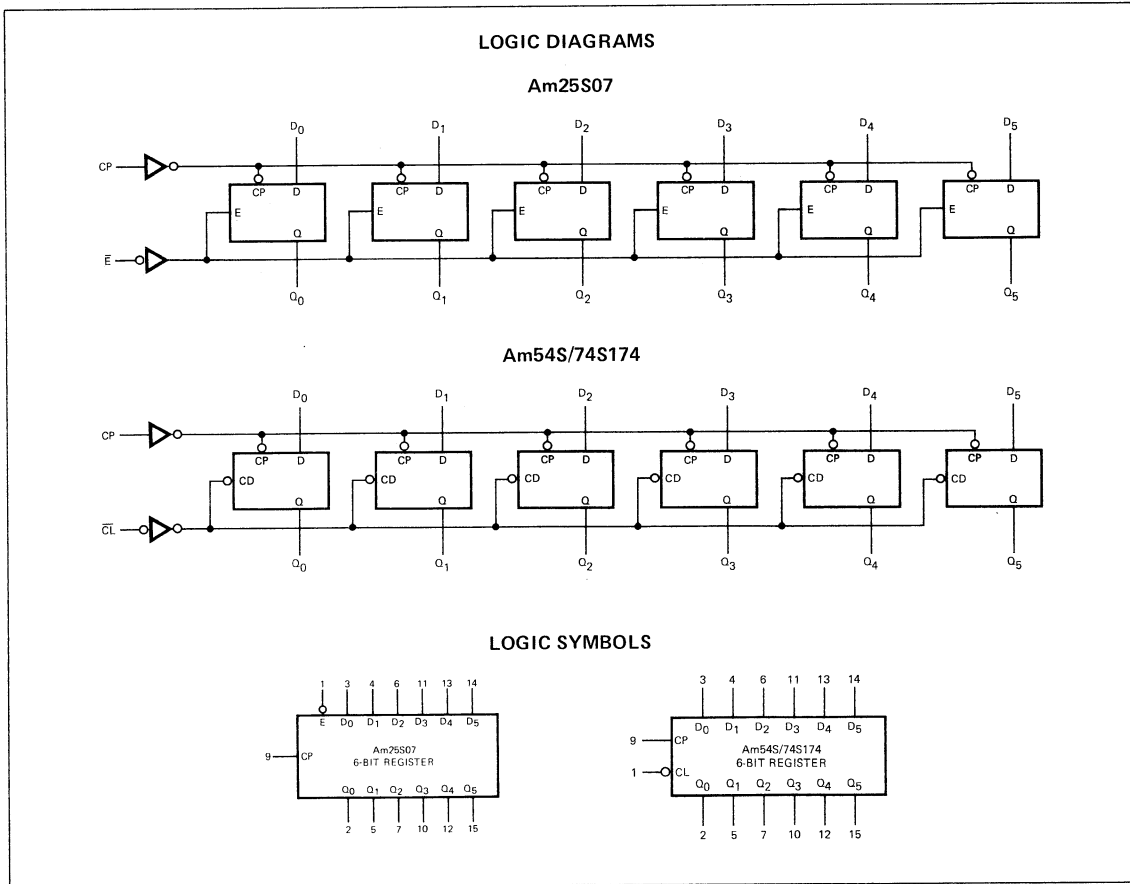


Figure 3. Logic Diagram and Logic Symbols for Am25S07 and Am54S/74S174 Registers.

FUNCTION TABLES

Am25S07, Am25S08

Inputs			Outputs	
\bar{E}	D_i	CP	Q_i	\bar{Q}_i
H	X	X	NC	NC
L	X	H	NC	NC
L	X	L	NC	NC
L	L	↑	L	H
L	H	↑	H	L

H = HIGH NC = No Change
 L = LOW X = Don't Care
 ↑ = LOW-to-HIGH Transition
 \bar{Q}_i on Am25S08 Only

Am54S/74S174, Am54S/74S175

INPUTS			OUTPUTS	
Clear	Clock	D_i	Q_i	\bar{Q}_i
L	X	X	L	H
H	L	X	NC	NC
H	H	X	NC	NC
H	↑	L	L	H
H	↑	H	H	L

H = HIGH X = Don't Care
 L = LOW NC = No Change
 ↑ = LOW-to-HIGH Transition
 Note: \bar{Q}_i on Am54S/74S175 only

Figure 4. Function Tables for Am25S07, Am25S08, Am54S/74S174 and Am54S/74S175 Registers.

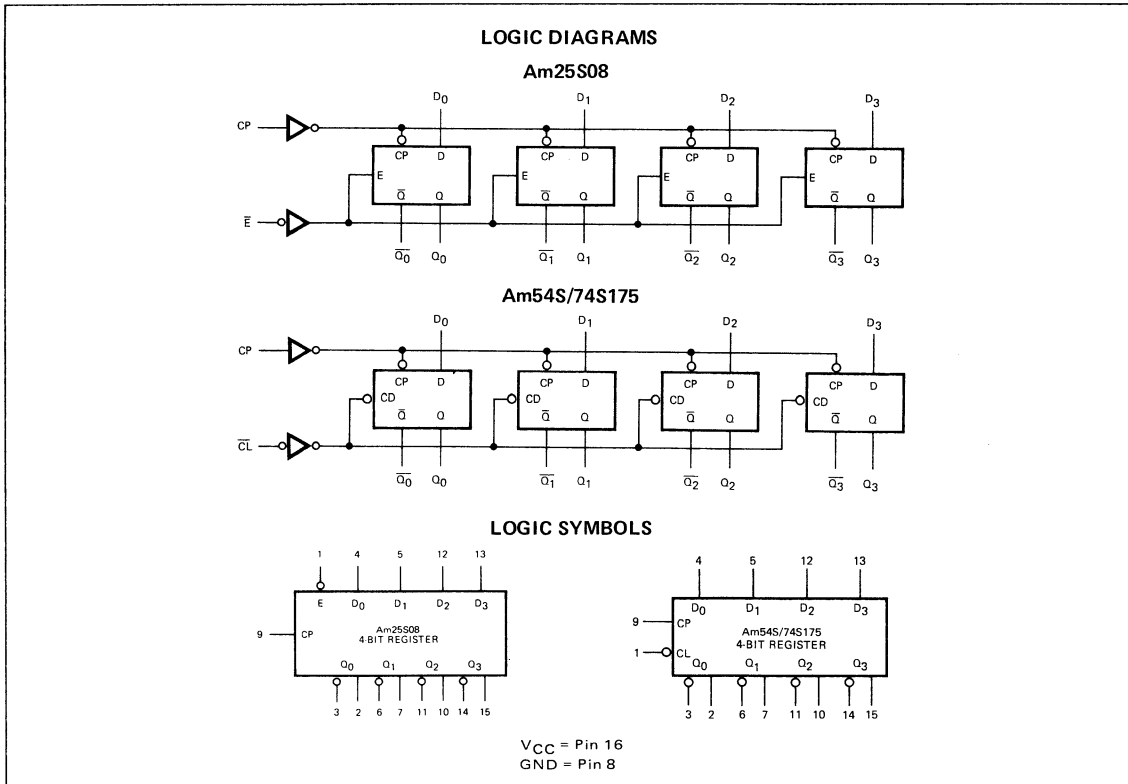


Figure 5. Logic Diagrams and Logic Symbols for Am25S08 and Am54S/74S175 Registers.

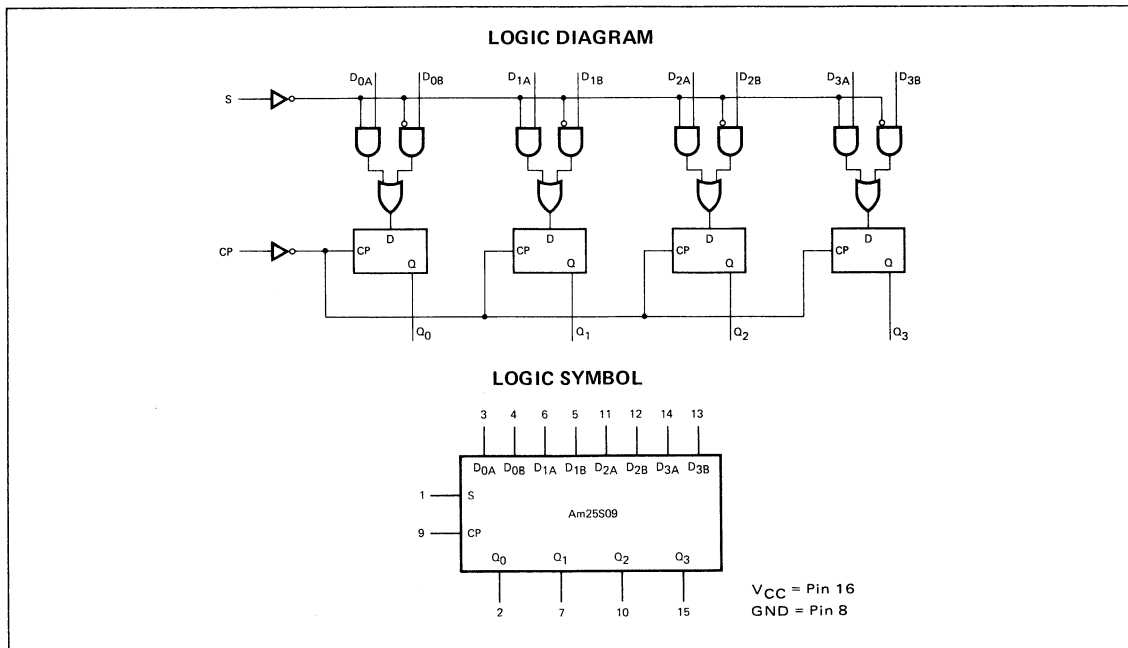


Figure 6. Logic Diagram and Logic Symbol for the Am25S09 Register.

Registers

THE Am25S09 FOUR-BIT REGISTER

This device is a four-bit register that features a quad two input multiplexer at the input of the register. This allows data to be stored in the register from either of two different data inputs. The logic diagram and logic symbol for this device is shown in Figure 6.

The register consists of four D-type positive edge triggered flip-flops with a buffered common clock and a two-input multiplexer connected to the D input of each flip-flop. A buffered common select line, S, controls the state of the four multiplexers. When the S select input is LOW, the A input word will be stored in the register. When the S select input is HIGH, the B input word will be stored in the register as shown in the Function Table of Figure 7. This ability to select the register input from either of two data sources is particularly useful in many applications. The data from one of two sources may be programmed or perhaps an operate/manual test capability is performed.

APPLICATIONS

Applications for these registers are numerous. By having both four-bit and six-bit versions available, many general and special data storage applications are easily handled. Also, the registers with the clock enable input provide a unique

capability for many high-speed synchronous systems. With so many Schottky TTL registers available, the digital designer now has the right register for each data storage application. Applications for the registers previously described are shown on the remaining pages.

FUNCTION TABLE				
SELECT S	CLOCK CP	DATA D _i A	INPUTS D _i B	OUTPUT Q _i
L	↑	L	X	L
L	↑	H	X	H
H	↑	X	L	L
H	↑	X	H	H

H = HIGH Voltage Level
 X = Don't Care
 ↑ = LOW-to-HIGH Transition

L = LOW Voltage Level
 i = 0, 1, 2, or 3

Figure 7. Function Table for the Am25S09 Register.

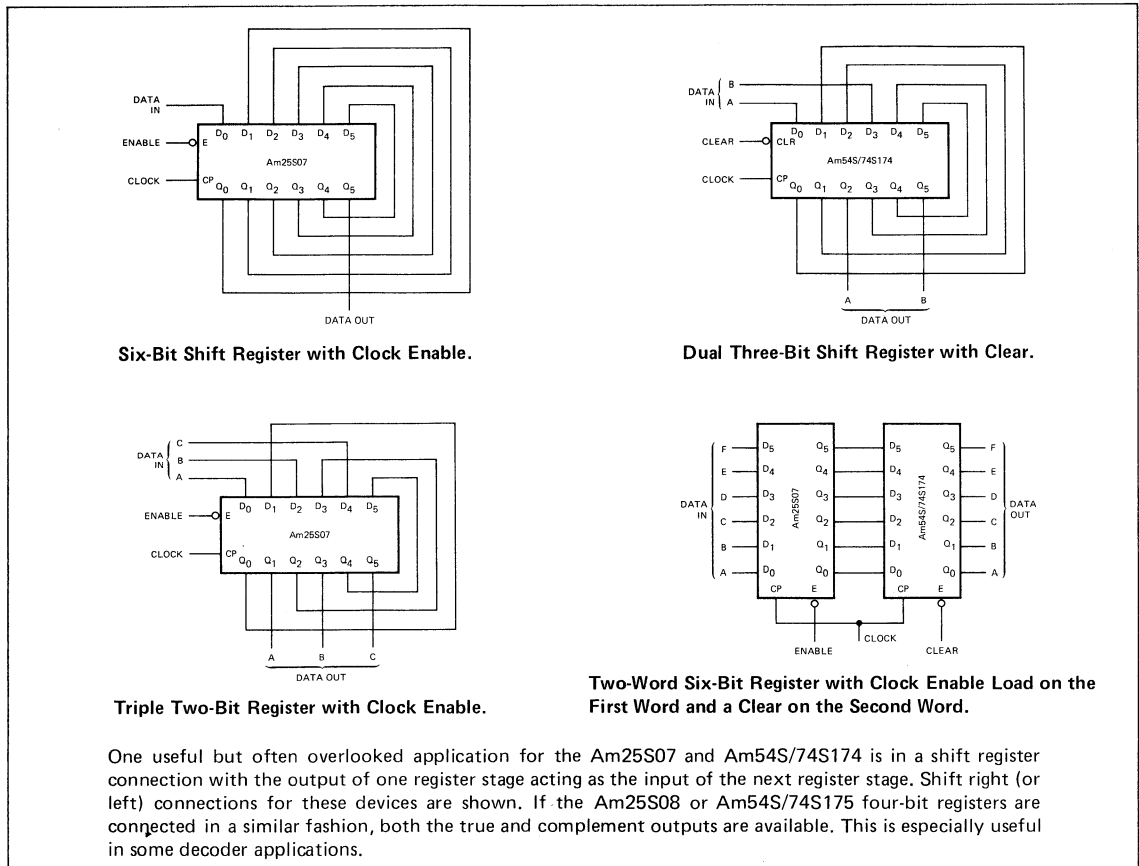
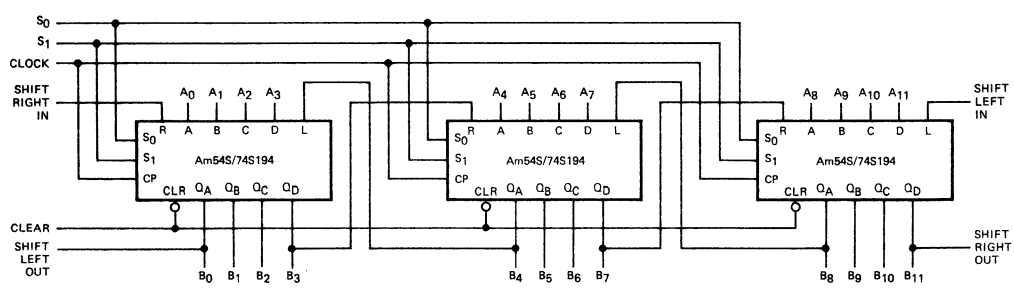
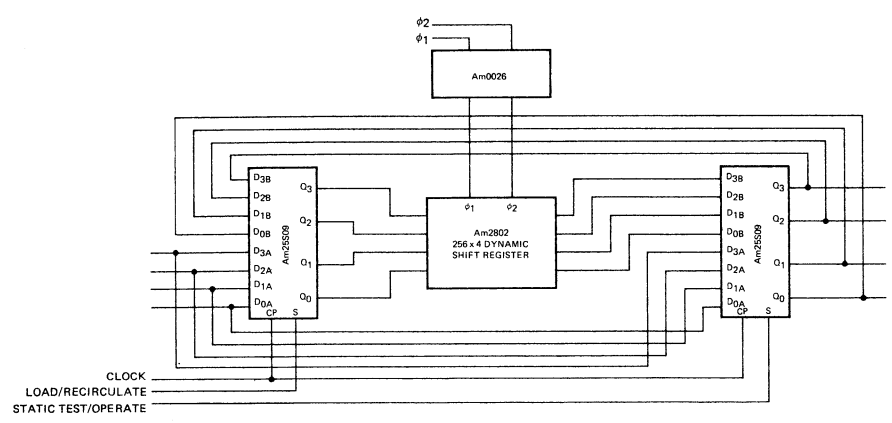


Figure 8. D-Type Registers Connected for Shifting.



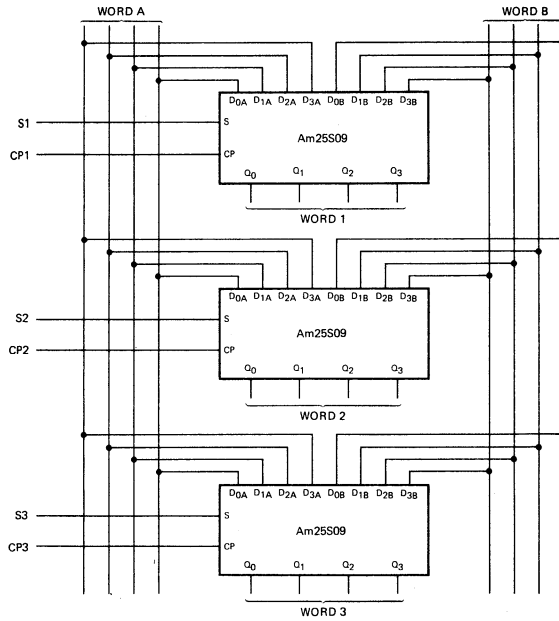
The normal shift register connection for long words using the Am54S/74S194 features shift-right, shift-left, parallel load or hold data modes. It can be connected to circulate data in either direction or shift in 0's or 1's at either end. The Am54S/74S195 is connected in a similar fashion, however, the device can shift data in only one direction. Although the Am54S/74S195 is called a shift-right register, it can be used to shift data left by relabeling the shift and parallel inputs and the Q outputs.

Figure 9. Connecting the Am54S/74S194 Shift Register for Longer Words.



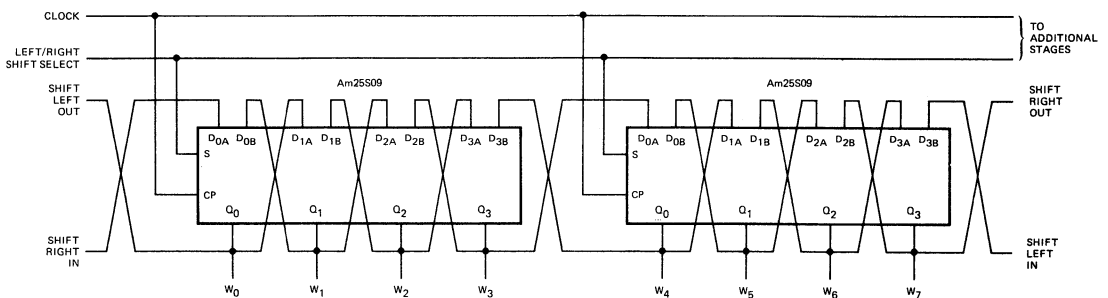
The Am25S09 can be used in a 256 x 4 memory system with load/recirculate control, and 1 x 4 static test capability for the system. This circuit is especially useful in digital filtering where special algorithms require a static single step operation for testing purposes. MOS interface is one STTL unit load at each end. The required pull-up and pull-down resistors are not shown.

Figure 10. Using the Am25S09 with Dynamic Shift Registers.



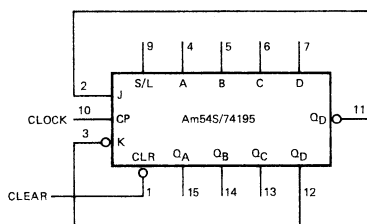
The Am25S09 used to store a word from either data bus A or data bus B.

Figure 11. Selective Bus Storage with the Am25S09 Register.



The Am25S09 can be used as a shift-left, shift-right register under control of a single select input. This connection can also be used as a clocked last-in, first-out (LIFO) memory. The output data is available in either serial or parallel form.

Figure 12. The Am25S09 as a LIFO Memory.



NORMAL DEFINITIONS

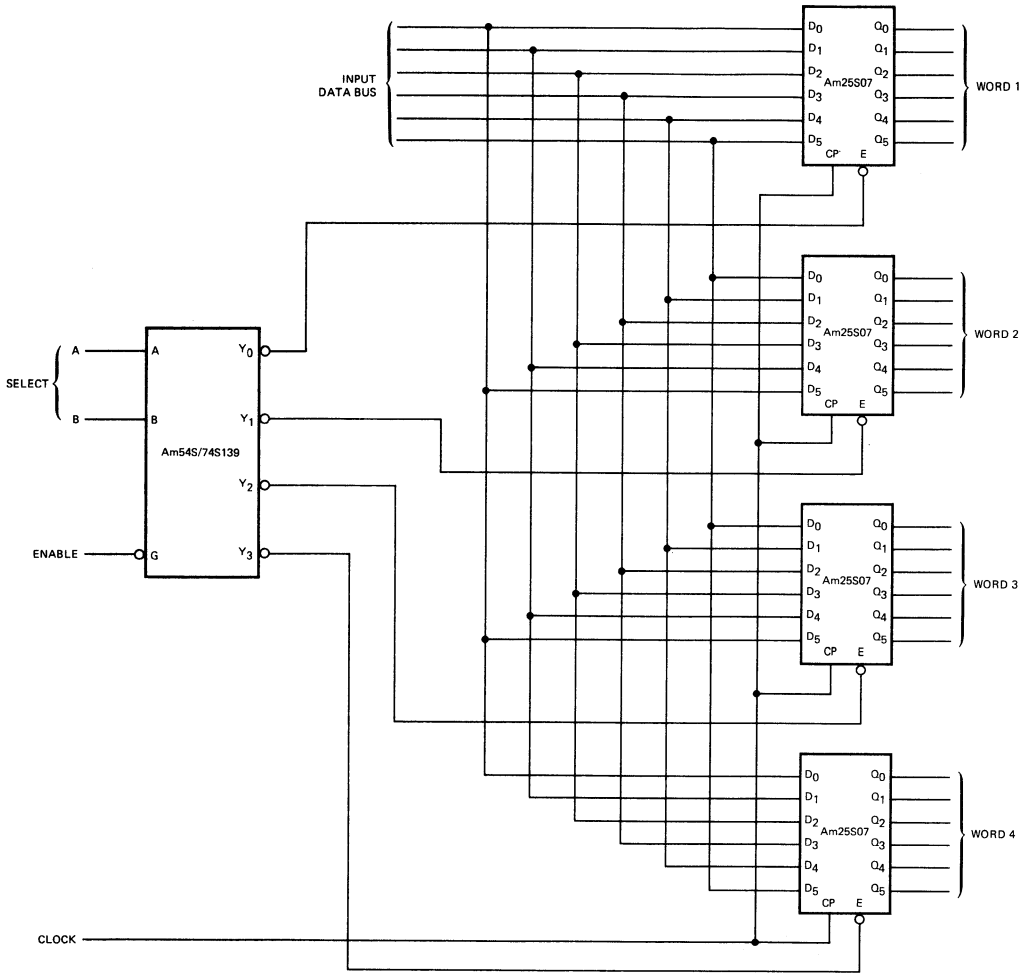
PIN NO.				Decimal
12	13	14	15	
2^3	2^2	2^1	2^0	
0	0	0	0	0
0	0	0	1	1
0	0	1	0	2
0	1	0	1	5
1	0	1	0	10
0	1	0	0	4
1	0	0	1	9
0	0	1	1	3
0	1	1	0	6
1	1	0	1	13
1	0	1	1	11
0	1	1	1	7
1	1	1	0	14
1	1	0	0	12
1	0	0	0	8
0	0	0	0	0

ALTERNATE DEFINITIONS

PIN NO.				Decimal
12	13	14	15	
2^0	2^1	2^2	2^3	
0	0	0	0	0
0	0	0	1	8
0	0	1	0	4
0	1	0	1	10
1	0	1	0	5
0	1	0	0	2
1	0	0	1	9
0	0	1	1	12
0	1	1	0	6
1	1	0	1	11
1	0	1	1	13
0	1	1	1	14
1	1	1	0	7
1	1	0	0	3
1	0	0	0	1
0	0	0	0	0

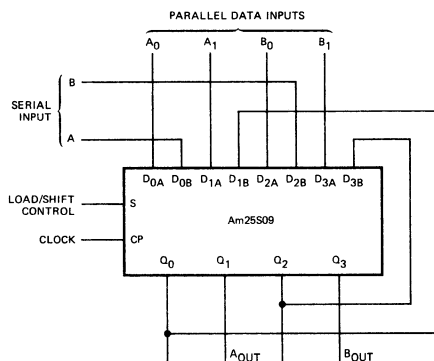
A high-speed modulo 15 linear feedback shift register takes advantage of the J and \bar{K} inputs on the Am54S/74S195. The "decimal" sequence is determined by the weight assigned to the output pins and many alternate definitions are possible. Registers of longer length can be built by cascading additional Am54S/74S195's. Binary state 15 (all 1's) is not self-correcting. The clear or parallel load should be used to initialize the register.

Figure 13. Pseudo-Random Feedback Registers.



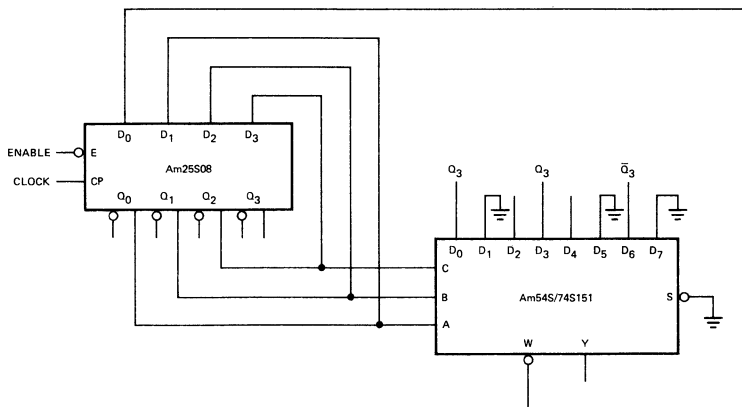
The clock enable on the Am25S07 or Am25S08 can be used to perform selective register loading from a common data bus. One-half of an Am54S/74S139 dual one-of-four decoder provides the select signals as controlled by the two-bit select field (A and B). The enable input (G) on the Am54S/74S139 can be used to inhibit loading of any of the four registers.

Figure 14. Selecting Data for One Register.



Often a need occurs to delay one or two signals by a few clock cycles. This example shows the Am25S09 providing two clock delays for two input data paths. In addition, a parallel preset (or clear) is available via the load/shift control for initialization. Also, the data delayed by one clock cycle is available if needed.

Figure 15. Dual Two-Bit Right-Shift Register with Full Parallel Load.

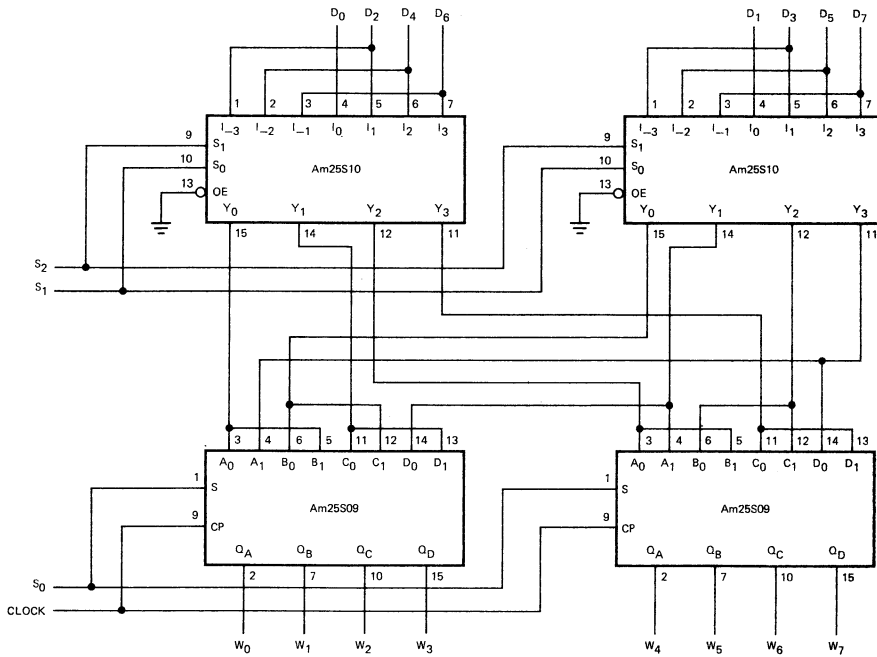


FUNCTION TABLE

Q ₃	Q ₂	Q ₁	Q ₀	D ₀	Mplx. State	Mplx. Input
0	0	0	0	1	0	Q ₃
0	0	0	1	1	1	0
0	0	1	1	1	3	Q ₃
0	1	1	1	0	7	0
1	1	1	0	1	6	\bar{Q}_3
1	1	0	1	1	5	0
1	0	1	1	0	3	Q ₃
0	1	1	0	0	6	\bar{Q}_3
1	1	0	0	0	4	1
1	0	0	0	0	0	Q ₃
0	0	0	0	1	0	Q ₃

The Am25S08 is shown combined with an Am54S/74S151 eight-input multiplexer to build a 4-bit shift counter. This technique provides the ability to design many unique codes. By using the Am54S/74S251 eight-input multiplexer with three state outputs, the same register can be used with interchangeable codes depending on which multiplexer output is enabled. The Am54S/74S195 can also be very useful in this application since both the Q_D and \bar{Q}_D outputs are available and the J and \bar{K} inputs can be tied to the multiplexer output to provide a D-type input. This device offers a direct clear as well as a parallel load for initialization to any counter state. However, the true and complement outputs are not available with the Am54S/74S195.

Figure 16. Shift Register Generates Unique Counting Codes.

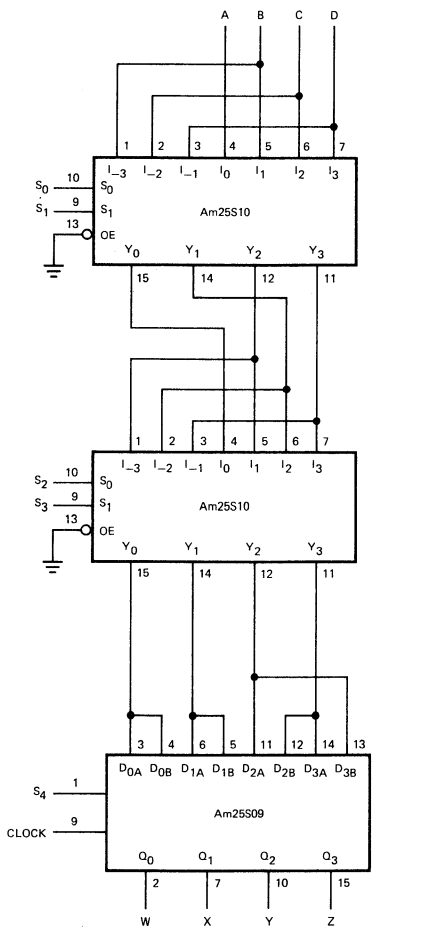


FUNCTION TABLE

S ₂	S ₁	S ₀	W ₀	W ₁	W ₂	W ₃	W ₄	W ₅	W ₆	W ₇
0	0	0	D ₀	D ₁	D ₂	D ₃	D ₄	D ₅	D ₆	D ₇
0	0	1	D ₇	D ₀	D ₁	D ₂	D ₃	D ₄	D ₅	D ₆
0	1	0	D ₆	D ₇	D ₀	D ₁	D ₂	D ₃	D ₄	D ₅
0	1	1	D ₅	D ₆	D ₇	D ₀	D ₁	D ₂	D ₃	D ₄
1	0	0	D ₄	D ₅	D ₆	D ₇	D ₀	D ₁	D ₂	D ₃
1	0	1	D ₃	D ₄	D ₅	D ₆	D ₇	D ₀	D ₁	D ₂
1	1	0	D ₂	D ₃	D ₄	D ₅	D ₆	D ₇	D ₀	D ₁
1	1	1	D ₁	D ₂	D ₃	D ₄	D ₅	D ₆	D ₇	D ₀

Two Am25S09 registers with the two input multiplexer can be used in conjunction with two Am25S10 four-bit shifters to implement an eight-bit full end around shifter (barrel shifter) with storage. The Function Table shows the data rotation for the various three-bit select field states.

Figure 17. Eight-Bit Full End Around Shift with Storage.

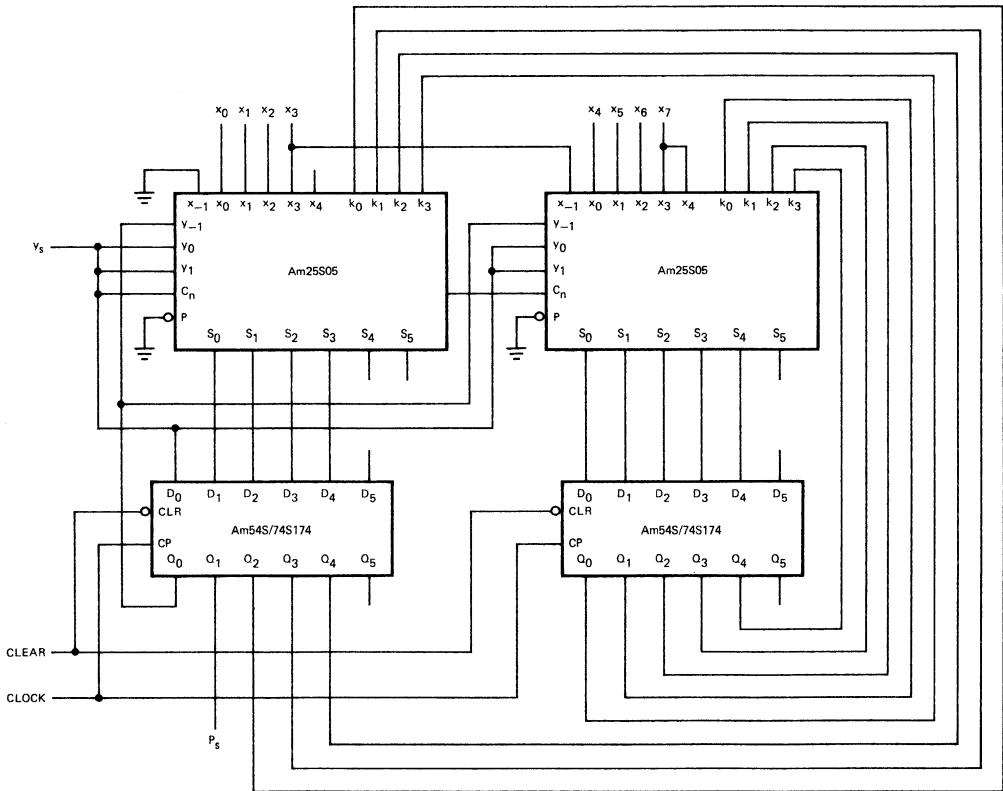


FUNCTION TABLE

State Number	Select					Output			
	S ₄	S ₃	S ₂	S ₁	S ₀	W	X	Y	Z
0	0	0	0	0	0	A	C	B	D
1	0	0	0	0	1	D	B	A	C
2	0	0	0	1	0	C	A	D	B
3	0	0	0	1	1	B	D	C	A
4	0	0	1	0	0	D	A	C	B
5	0	0	1	0	1	C	D	B	A
6	0	0	1	1	0	B	C	A	D
7	0	0	1	1	1	A	B	D	C
8	0	1	0	0	0	B	D	A	C
9	0	1	0	0	1	A	C	D	B
10	0	1	0	1	0	D	B	C	A
11	0	1	0	1	1	C	A	B	D
12	0	1	1	0	0	C	B	D	A
13	0	1	1	0	1	B	A	C	D
14	0	1	1	1	0	A	D	B	C
15	0	1	1	1	1	D	C	A	B
16	1	0	0	0	0	State 9			
17	1	0	0	0	1	State 10			
18	1	0	0	1	0	State 11			
19	1	0	0	1	1	State 8			
20	1	0	1	0	0	D	A	B	C
21	1	0	1	0	1	C	D	A	B
22	1	0	1	1	0	B	C	D	A
23	1	0	1	1	1	A	B	C	D
24	1	1	0	0	0	State 3			
25	1	1	0	0	1	State 0			
26	1	1	0	1	0	State 1			
27	1	1	0	1	1	State 2			
28	1	1	1	0	0	C	B	A	D
29	1	1	1	0	1	B	A	D	C
30	1	1	1	1	0	A	D	C	B
31	1	1	1	1	1	D	C	B	A

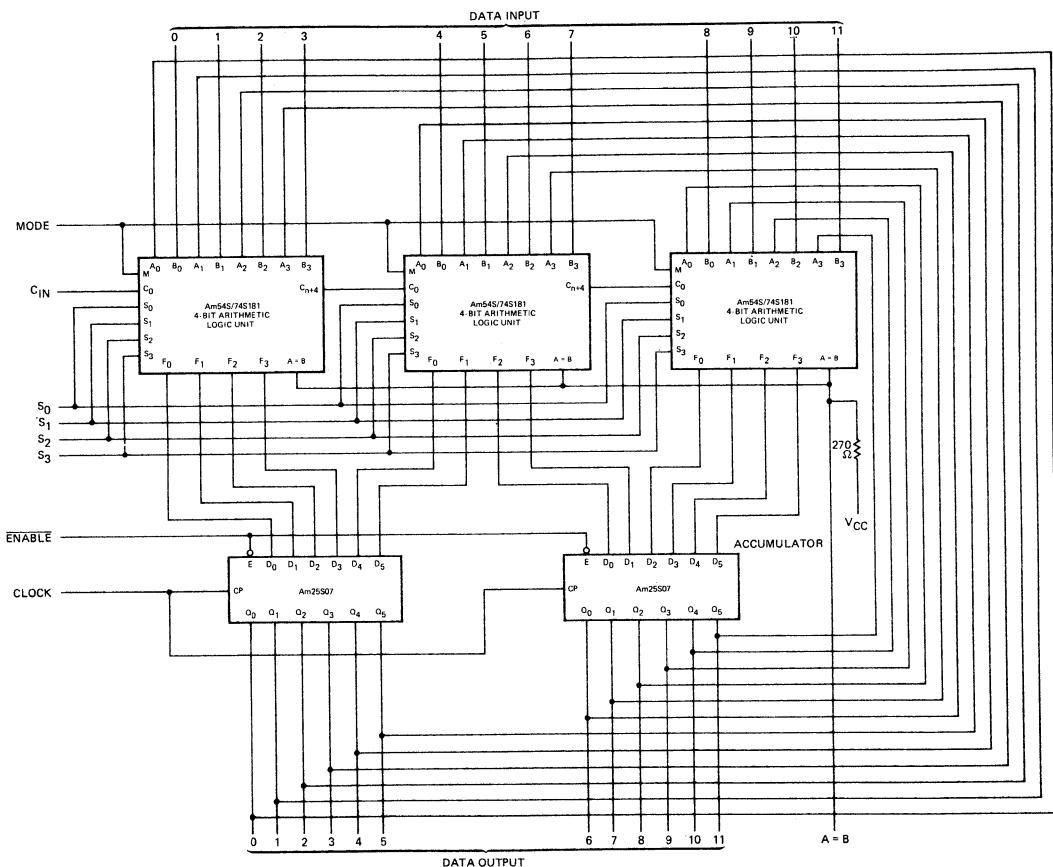
Two Am25S10 four-bit shifters are used in conjunction with an Am25S09 register to perform all possible permutations on four inputs. The number of combinations possible on n items is given as n!. Thus, for n equal to 4, 24 combinations are possible. The Function Table shows all 32 combinations of the 5-bit select code including the 8 redundant states. The four outputs are stored via the Am25S09 register. This connection can be particularly useful in security systems and certain random number generation schemes. The eight redundant states can be placed at other select field locations through proper design.

Figure 18. Perform all Permutations on Four Inputs.



The Am54S/74S174 register is used to hold the running partial product of an 8-bit serial-parallel 2's complement multiplier. The Am25S05 2's complement multiplier provides the combinatorial logic of Booth's algorithm. This connection multiplies a parallel X word by a serial Y word (LSB first) to give a resultant serial product word P (LSB first). If the entire product is to be taken in serial form, the Y input sign bit must be extended for the total number of clock cycles. For example, an 8-bit X multiplied by an 8-bit Y requires 16 clock cycles and the Y's sign must be extended for the last eight clock cycles.

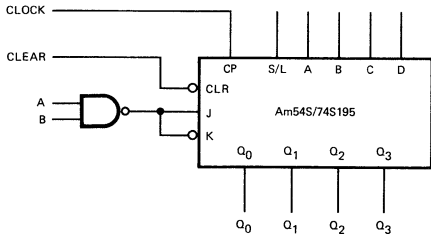
Figure 19. Serial-Parallel Multiplication.



The clock enable feature of the Am25S07 can be used to advantage in a high-speed arithmetic logic accumulator. Clearing is accomplished via one of the 16 select states of the Am54S/74S181.

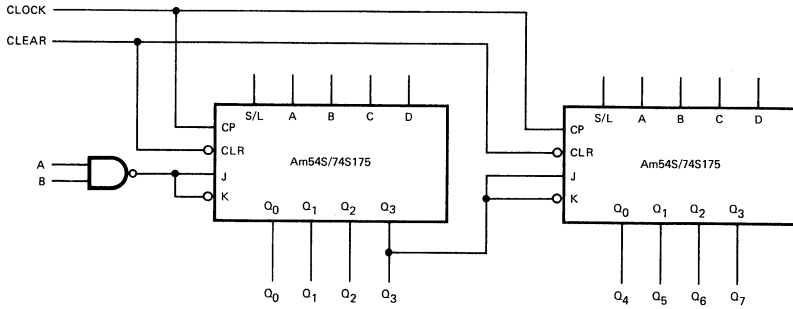
Figure 20. High-Speed Arithmetic Accumulator.

FUNCTION TABLE



Divide By	Input A	Input B	Output
2	Q ₀	H	Q ₀
3	Q ₀	Q ₁	Q ₁
4	Q ₁	H	Q ₁
5	Q ₁	Q ₂	Q ₂
6	Q ₂	H	Q ₂
7	Q ₂	Q ₃	Q ₃
8	Q ₃	H	Q ₃

H = HIGH



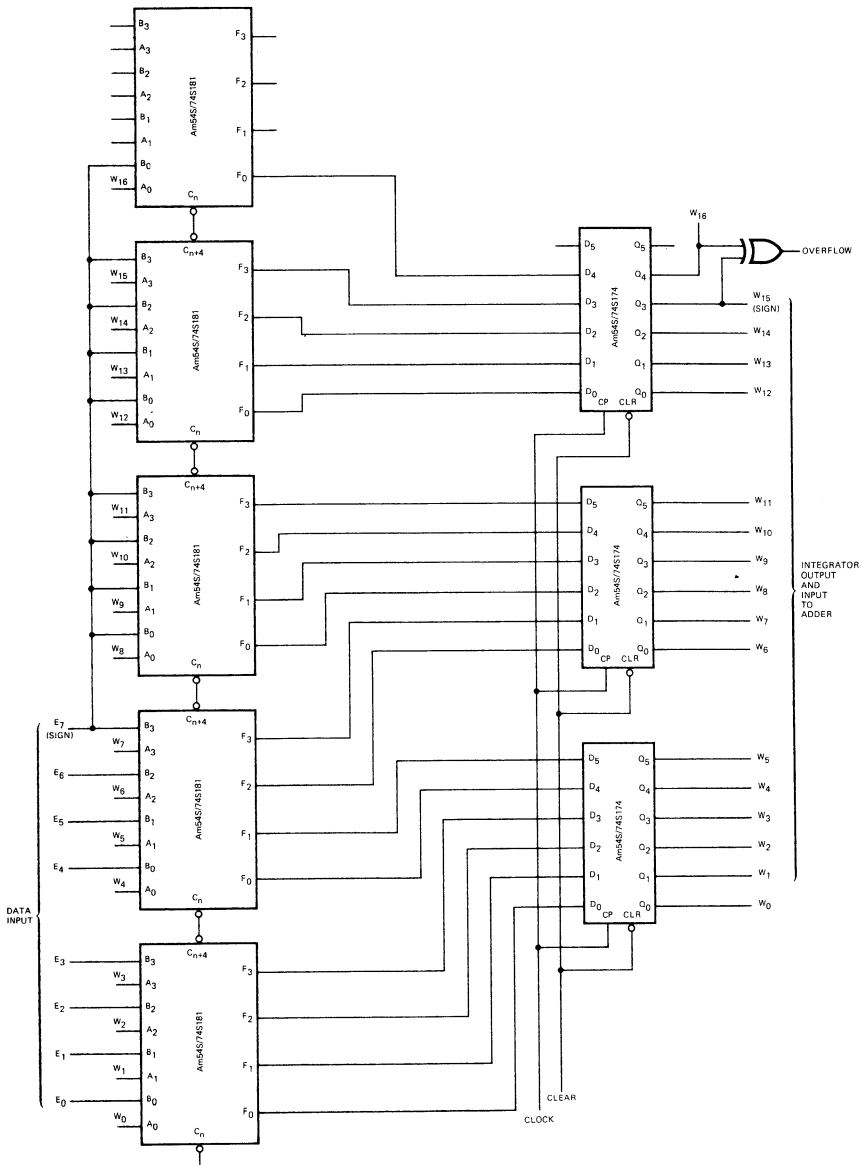
FUNCTION TABLE

Divide By	Input A	Input B	Output
9	Q ₃	Q ₄	Q ₄
10	Q ₄	H	Q ₄
11	Q ₄	Q ₅	Q ₅
12	Q ₅	H	Q ₅
13	Q ₅	Q ₆	Q ₆
14	Q ₆	H	Q ₆
15	Q ₆	Q ₇	Q ₇
16	Q ₇	H	Q ₇

H = HIGH

The Am54S/74S195 shift register can be used in conjunction with one two input NAND gate to form a divider chain of any length. The output waveform will be approximately a 50% duty cycle. One shift register can be used to cover the range of $\div 2$ through $\div 8$. Using two shift registers, the range of $\div 9$ through $\div 16$ is covered. If three shift registers are used, the range of $\div 17$ through $\div 24$ is possible; and so forth.

Figure 21. Shift Register Counter of any Length.



Am54S/74S181 in Add Mode.

The Am54S/74S174 can be used as the accumulator register in a high-speed digital integrator. The data input is an 8-bit two's complement number while the data output is a 16-bit two's complement number. Provision is made to detect integrator overflow. The DC gain of the integrator for a single input sample is

$\frac{1}{256}$. Thus, the transfer function of this integrator is given as

$$W = \sum_{n=0}^{\infty} \frac{E_n}{256}$$

A typical application for such an integrator is to smooth a video signal. For example, a bipolar analog signal is converted to an eight-bit 2's complement representation, via an A/D converter, passed through the integrator, and then reconverted to an analog signal via a D/A converter.

Figure 22. Digital Integrator.

Am25S09

Quad Two-Input, High-Speed Register

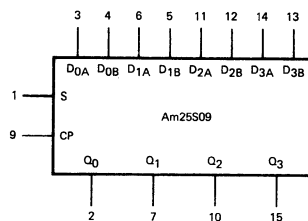
Distinctive Characteristics

- Four-bit register accepts data from one of two 4-bit input fields.
- Edge triggered clock action
- High-speed Schottky technology.
- 100% reliability assurance testing in compliance with MIL-STD-883.
- Electrically tested and optically inspected dice for the assemblers of hybrid products.

FUNCTIONAL DESCRIPTION

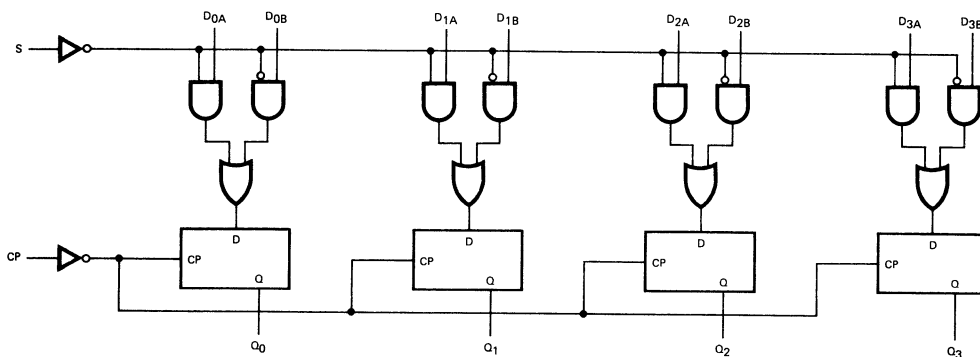
The Am25S09 is a dual port high-speed, four-bit register using advanced Schottky technology to reduce the effect of transistor storage time. The register consists of four D flip-flops with a buffered common clock, and a two-input multiplexer at the input of each flip-flop. A common select line, S, controls the four multiplexers. Data on the four inputs selected by the S line is stored in the four flip-flops at the clock LOW-to-HIGH transition. When the S input is LOW, the D_{1A} input data will be stored in the register. When the S input is HIGH, the D_{1B} input data will be stored in the register.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

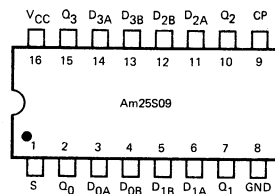
LOGIC DIAGRAM



ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM25S09PC
Hermetic DIP	0°C to +70°C	AM25S09DC
Dice	0°C to +70°C	AM25S09XC
Hermetic DIP	-55°C to +125°C	AM25S09DM
Hermetic Flat Pak	-55°C to +125°C	AM25S09FM
Dice	-55°C to +125°C	AM25S09XM

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 V to +7 V
DC Voltage Applied to Outputs for High Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +5.5 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am25S09XC	T _A = 0°C to +70°C	V _{CC} = 5.0 V ± 5% (COM'L)	MIN. = 4.75 V	MAX. = 5.25 V
Am25S09XM	T _A = -55°C to +125°C	V _{CC} = 5.0 V ± 10% (MIL)	MIN. = 4.5 V	MAX. = 5.5 V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1.0mA V _{IN} = V _{IH} or V _{IL}	COM'L	2.7	3.4	Volts
			MIL	2.5	3.4	
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20.0mA V _{IN} = V _{IH} or V _{IL}		0.3	0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{IL} (Note 3)	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V			-2.0	mA
I _{IH} (Note 3)	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			50	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX.	-40		-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)		75	120	mA

- Notes: 1. For conditions shown as MIN. or MAX. use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
 4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 5. Measured with Select and Clock inputs at 4.5V; all data inputs at 0V; all outputs open.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	Clock to Q HIGH	V _{CC} = 5.0V, C _L = 15pF, R _L = 280Ω		8	12	ns
t _{PHL}	Clock to Q LOW			11.5	17	ns
t _{pw}	Clock Pulse Width			7		ns
t _s	Data Set-up Time			5.5		ns
t _s	Select Input Set-up Time			10		ns
t _h	Data Hold Time			3		ns
t _h	Select Input Hold Time			3		ns

FUNCTION TABLE

SELECT S	CLOCK CP	DATA D _{iA}	INPUTS D _{iB}	OUTPUT Q _i
L	↑	L	X	L
L	↑	H	X	H
H	↑	X	L	L
H	↑	X	H	H

H = HIGH Voltage Level
X = Don't Care
↑ = LOW-to-HIGH Transition

L = LOW Voltage Level
i = 0, 1, 2, or 3

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
S	1	1	—	—
Q ₀	2	—	20	10
D _{0A}	3	1	—	—
D _{0B}	4	1	—	—
D _{1B}	5	1	—	—
D _{1A}	6	1	—	—
Q ₁	7	—	20	10
GND	8	—	—	—
CP	9	1	—	—
Q ₂	10	—	20	10
D _{2A}	11	1	—	—
D _{2B}	12	1	—	—
D _{3B}	13	1	—	—
D _{3A}	14	1	—	—
Q ₃	15	—	20	10
V _{CC}	16	—	—	—

A Schottky TTL Unit Load is defined as 50 μ A measured at 2.7 V HIGH and -2.0 mA measured at 0.5 V LOW.

DEFINITION OF FUNCTIONAL TERMS

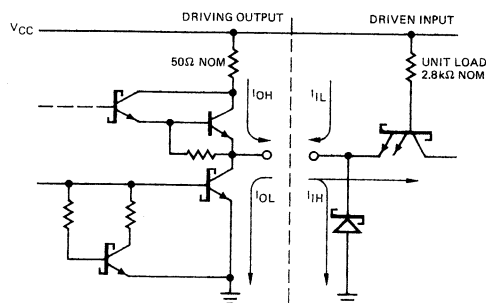
D_{0A}, D_{1A}, D_{2A}, D_{3A} The "A" word into the two-input multiplexer of the D flip-flops.

D_{0B}, D_{1B}, D_{2B}, D_{3B} The "B" word into the two-input multiplexer of the D flip-flops.

Q₀, Q₁, Q₂, Q₃ The outputs of the four D-type flip-flops of the register.

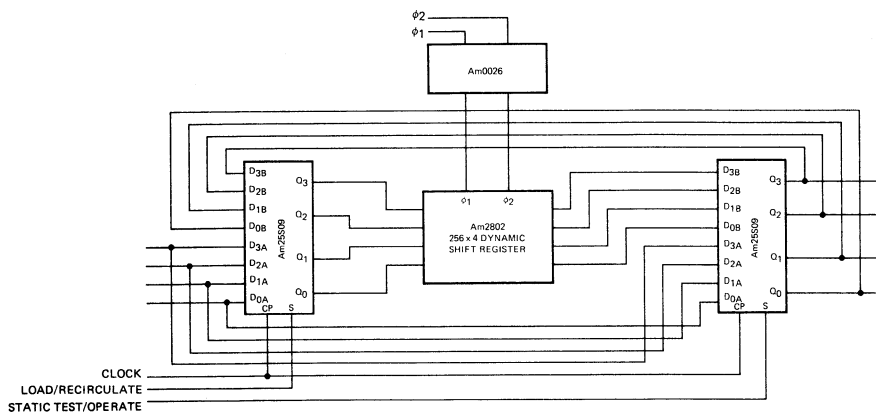
S Select. When the select is LOW, the A word is applied to the D inputs of the flip-flops. When the select is HIGH the B word is applied to the D inputs of the flip-flops.

CP Clock Pulse. Clock pulse for the register. Enters data on the LOW-to-HIGH transition of the clock line.

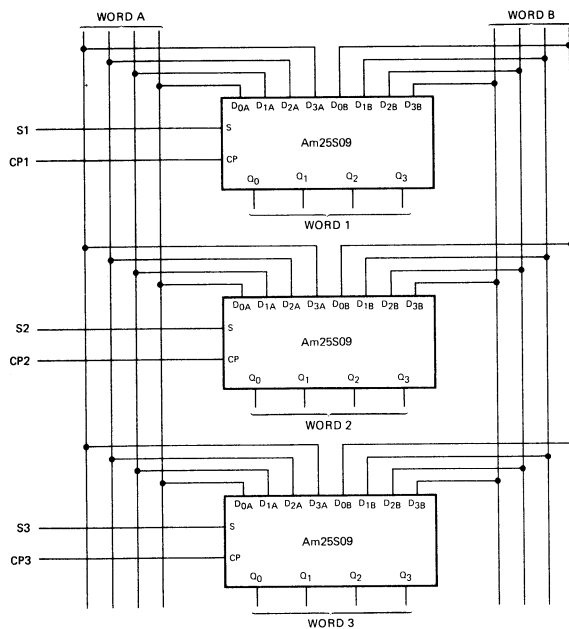
SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS

Note: Actual current flow direction shown

APPLICATIONS

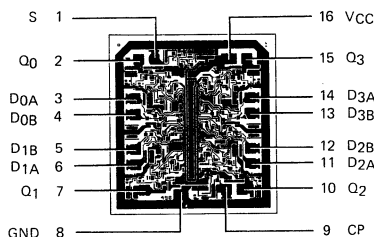


Am25S09 used in 258 x 4 memory system with load/recirculate control, and 1 x 4 static test capability for the system. MOS interface is one load at each end. This circuit is especially useful in digital filtering where special algorithms require a static single step operation for testing purposes.



Am25S09 used to store a word from either data bus A or data bus B.

Metallization and Pad Layout



DIE SIZE: 0.067" X 0.073"

4

Am25S10

Four-Bit Shifter With Three-State Outputs

Distinctive Characteristics

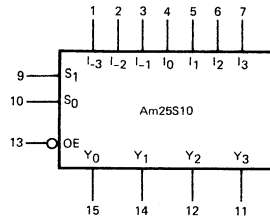
- Shifts 4-bits of data to 0, 1, 2 or 3 places under control of two select lines.
- Three-state outputs for bus organized systems.
- 6.5 ns typical data propagation delay
- Alternate source is 54S/74S350
- 100% reliability assurance testing in compliance with MIL-STD-883.

FUNCTIONAL DESCRIPTION

The Am25S10 is a combinatorial logic circuit that accepts a four-bit data word and shifts the word 0, 1, 2 or 3 places. The number of places to be shifted is determined by a two-bit select field S_0 and S_1 . An active-LOW enable controls the three-state outputs. This feature allows expansion of shifting over a larger number of places with one delay.

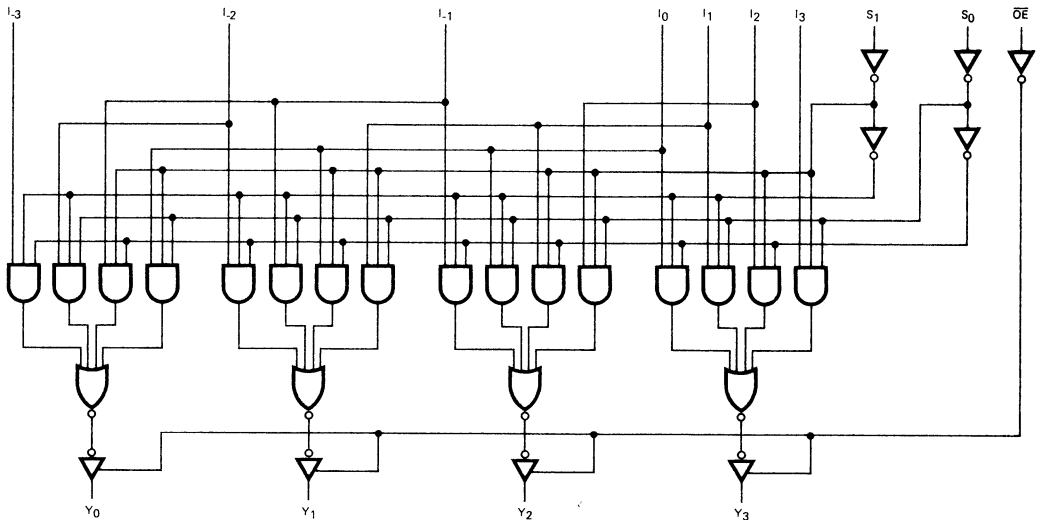
By suitable interconnection, the Am25S10 can be used to shift any number of bits any number of places up or down. Shifting can be logical, with logic zeroes pulled in at either or both ends of the shifting field; arithmetic, where the sign bit is repeated during a shift down; or end around, where the data word forms a continuous loop.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

LOGIC DIAGRAM



ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM25S10PC
Hermetic DIP	0°C to +70°C	AM25S10DC
Dice	0°C to +70°C	AM25S10XC
Hermetic DIP	-55°C to +125°C	AM25S10DM
Hermetic Flat Pak	-55°C to +125°C	AM25S10FM
Dice	-55°C to +125°C	AM25S10XM

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 V to +7 V
DC Voltage Applied to Outputs for High Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +5.5 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am25S10XC	T _A = 0°C to +70°C	V _{CC} = 5.0 V ± 5% (COM'L)	MIN. = 4.75 V	MAX. = 5.25 V
Am25S10XM	T _A = -55°C to +125°C	V _{CC} = 5.0 V ± 10% (MIL)	MIN. = 4.5 V	MAX. = 5.5 V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., V _{IN} = V _{IH} or V _{IL}	XM I _{OH} = -2mA	2.4	3.4		Volts
			XC I _{OH} = -6.5mA	2.4	3.2		
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts	
I _{IL} (Note 3)	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5 V			-2.0	mA	
I _{IH} (Note 3)	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7 V			50	μA	
I _O	Off State (High Impedance) Output Current	V _{CC} = MAX., V _O = 2.4 V V _O = 0.5 V			50	μA	
					-50		
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5 V			1.0	mA	
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 0.0 V	-40		-100	mA	
I _{CC}	Power Supply Current	V _{CC} = MAX., All outputs open, All inputs = GND		60	85	mA	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0 V, 25°C ambient and maximum loading.
 3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
 4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	Data Input to Output	V _{CC} = 5.0 V, C _L = 15 pF, R _L = 280 Ω		5	7.5	ns
t _{PHL}				8	12	
t _{PLH}	Select to Output			11	17	ns
t _{PHL}				13	20	
t _{ZH}	Output Control \overline{OE} to Output				19.5	ns
t _{ZL}					21	
t _{HZ}	Output Control \overline{OE} to Output	V _{CC} = 5 V, C _L = 5 pF, R _L = 280 Ω		5	8	ns
t _{LZ}				10	15	

DEFINITION OF FUNCTIONAL TERMS

I_i The seven data inputs of the shifter.

\overline{OE} Enable. When the enable is HIGH, the four outputs are in the high impedance state. When the enable is LOW, the selected I_j inputs are present at the outputs.

S_0, S_1 Select inputs. Controls the number of places the inputs are shifted.

Y_i The four outputs of the shifter.

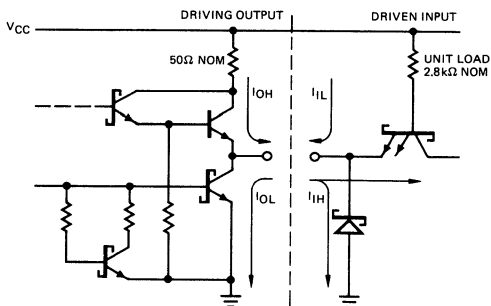
LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load (Note 1)	Fan-out	
			Output HIGH XM	Output LOW XC
I ₃	1	1	-	-
I ₂	2	1.5	-	-
I ₁	3	1.5	-	-
I ₀	4	1.5	-	-
I ₁	5	1.5	-	-
I ₂	6	1.5	-	-
I ₃	7	1	-	-
GND	8	-	-	-
S ₁	9	1	-	-
S ₀	10	1	-	-
Y ₃	11	-	40	130
Y ₂	12	-	40	130
\overline{OE}	13	1	-	-
Y ₁	14	-	40	130
Y ₀	15	-	40	130
V _{CC}	16	-	-	-

A Schottky TTL Unit Load is defined as 50 μ A measured at 2.7 V HIGH and -2.0mA measured at 0.5V LOW.

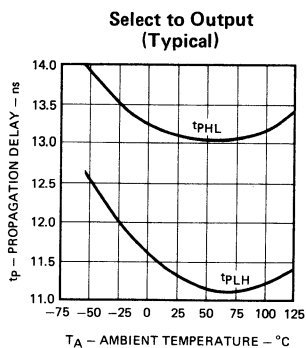
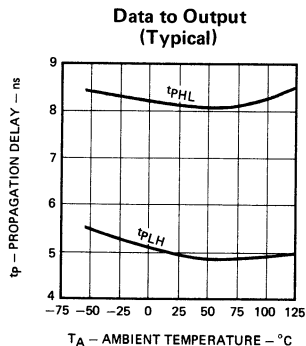
Note: 1. The fan-in on I₂, I₁, I₀, I₁ and I₂ will not exceed 1.5 Unit Loads when measured at V_{IL} = 0.5 V. As V_{IL} is decreased to 0 V, the input current I_{IL} MAX. increases to -4, -6, -8, -6 and -4 mA respectively due to the decrease in current sharing with the internal select buffer outputs.

SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

PERFORMANCE CURVES SWITCHING CHARACTERISTICS



LOGIC EQUATIONS

$$Y_0 = \overline{S_0} \overline{S_1} I_0 + S_0 \overline{S_1} I_1 + \overline{S_0} S_1 I_2 + S_0 S_1 I_3$$

$$Y_1 = \overline{S_0} \overline{S_1} I_1 + S_0 \overline{S_1} I_0 + \overline{S_0} S_1 I_1 + S_0 S_1 I_2$$

$$Y_2 = \overline{S_0} \overline{S_1} I_2 + S_0 \overline{S_1} I_1 + \overline{S_0} S_1 I_0 + S_0 S_1 I_1$$

$$Y_3 = \overline{S_0} \overline{S_1} I_3 + S_0 \overline{S_1} I_2 + \overline{S_0} S_1 I_1 + S_0 S_1 I_0$$

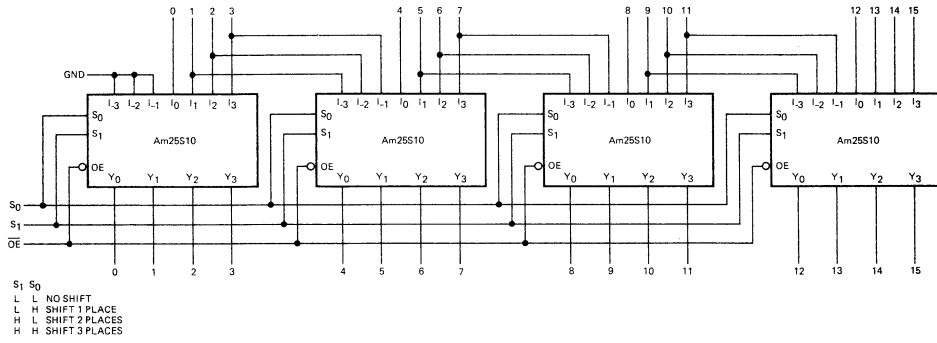
Note: For additional information, see page 5-54

TRUTH TABLE

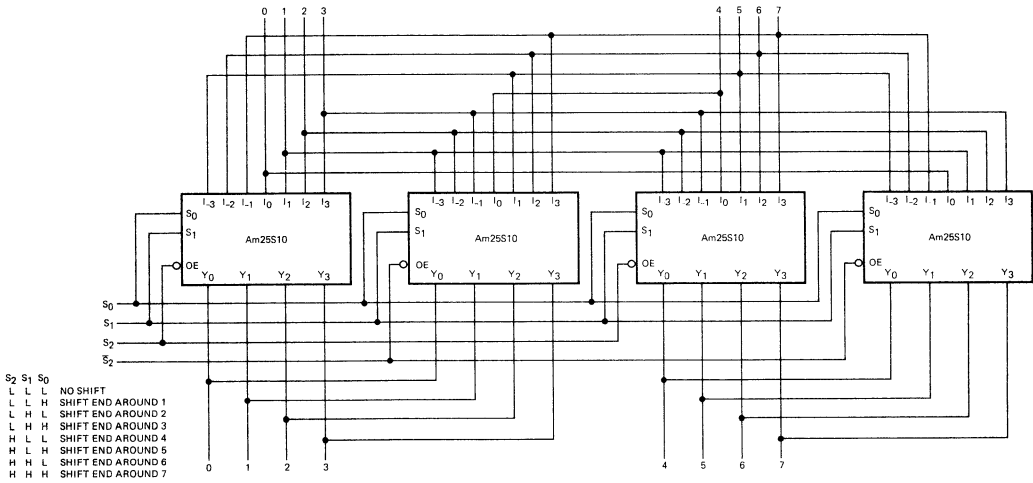
\overline{OE}	S ₁	S ₀	I ₃	I ₂	I ₁	I ₀	I ₁	I ₂	I ₃	Y ₃	Y ₂	Y ₁	Y ₀
H	X	X	X	X	X	X	X	X	X	Z	Z	Z	Z
L	L	L	D ₃	D ₂	D ₁	D ₀	X	X	X	D ₃	D ₂	D ₁	D ₀
L	L	H	X	D ₂	D ₁	D ₀	D ₋₁	X	X	D ₂	D ₁	D ₀	D ₋₁
L	H	L	X	X	D ₁	D ₀	D ₋₁	D ₋₂	X	D ₁	D ₀	D ₋₁	D ₋₂
L	H	H	X	X	X	D ₀	D ₋₁	D ₋₂	D ₋₃	D ₀	D ₋₁	D ₋₂	D ₋₃

H = HIGH
 L = LOW
 D_n at input I_n may be either HIGH or LOW and output Y_m will follow the selected D_n input level.
 X = Don't Care
 Z = High Impedance State

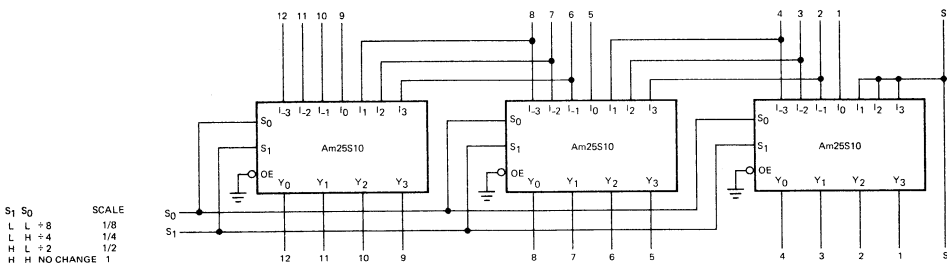
APPLICATIONS



16-Bit Shift-Up 0, 1, 2, or 3 Places

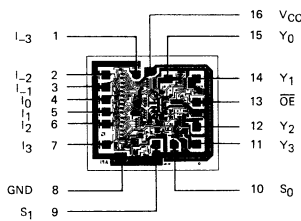


8-Bit End Around Shift 0, 1, 2, 3, 4, 5, 6, 7 Places



13-Bit 2's Complement Scaler

Metallization and Pad Layout



4

Am25S10 FOUR-BIT SHIFTER

By John R. Mick

INTRODUCTION

The Am25S10 is a high-speed MSI combinatorial logic block built using advanced Schottky technology. The device has the ability to shift four bits of data 0, 1, 2 or 3 places. The Am25S10 has two select lines that are decoded internally to determine the number of places the data is shifted. The device has seven data inputs I_{-3} , I_{-2} , I_{-1} , I_0 , I_1 , I_2 , and I_3 and 4 three-state data outputs Y_0 , Y_1 , Y_2 , and Y_3 as shown in the logic symbol diagram of Figure 1. The three-state outputs allow several devices to be bus organized for shifts of more than three places with a single level device propagation delay time. The three-state outputs are controlled by a single buffered active-LOW output control \overline{OE} . When the output control is LOW, the data outputs will follow the selected data inputs. When the output control is HIGH, the data outputs offer a high-impedance to the data bus.

FUNCTIONAL DESCRIPTION

The logic equations describing the output shifting capability of the Am25S10 when the output control is LOW are:

$$Y_0 = \overline{S_0} \overline{S_1} I_0 + S_0 \overline{S_1} I_{-1} + \overline{S_0} S_1 I_{-2} + S_0 S_1 I_{-3}$$

$$Y_1 = \overline{S_0} \overline{S_1} I_1 + S_0 \overline{S_1} I_0 + \overline{S_0} S_1 I_{-1} + S_0 S_1 I_{-2}$$

$$Y_2 = \overline{S_0} \overline{S_1} I_2 + S_0 \overline{S_1} I_1 + \overline{S_0} S_1 I_0 + S_0 S_1 I_{-1}$$

$$Y_3 = \overline{S_0} \overline{S_1} I_3 + S_0 \overline{S_1} I_2 + \overline{S_0} S_1 I_1 + S_0 S_1 I_0$$

From these equations it is seen that each output is operationally equivalent to a four-input multiplexer with the inputs connected such that the select code generates successive

one-bit shifts of the input data word. The logic diagram of Figure 2 shows the internal connection of each multiplexer with respect to the seven data inputs. Because of this internal connection scheme, several devices can be connected to perform shifts of 0, 1, 2, or 3 places on words of any length.

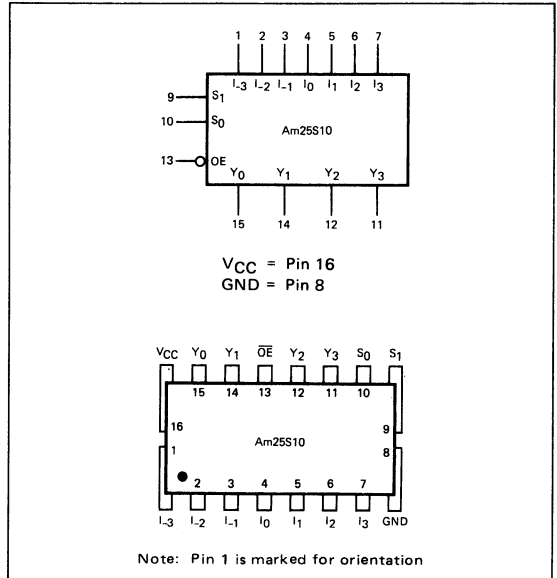


Figure 1. Logic Symbol and Connection Diagram.

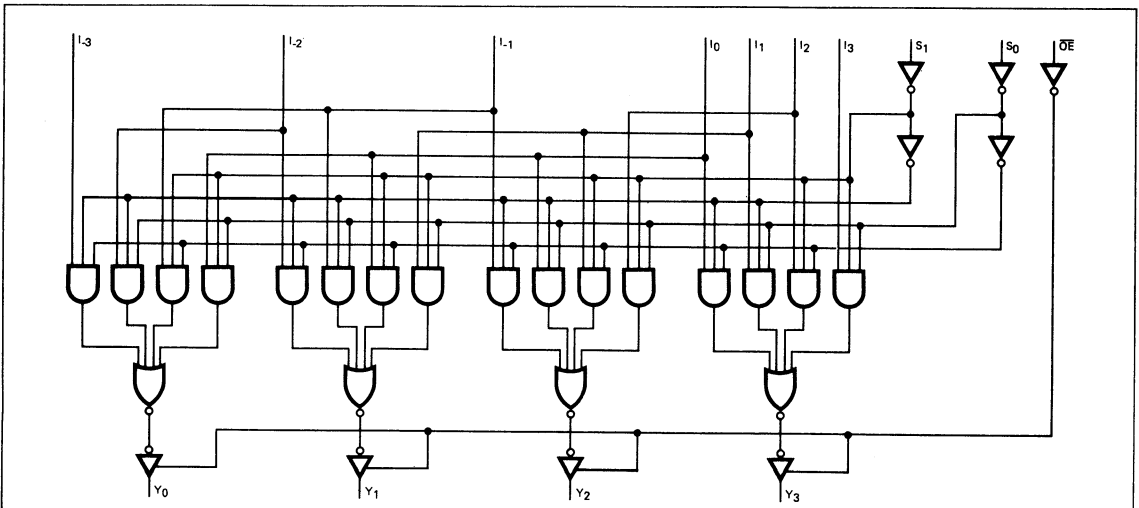


Figure 2. Logic Diagram of the Am25S10.

The operation of the Am25S10 is pictorially depicted in Figure 3. Here, the four shift positions of the data outputs with respect to the data inputs are shown via the dashed lines for the four possible select codes. Figure 4 shows a similar operation only the notation now represents a seven-bit input word A_0 through A_6 . The output code for each of the select field combinations applied to the S_0 and S_1 inputs is shown in the accompanying Function Table. In addition, the four outputs Y_0 through Y_3 can be forced to the high-impedance state by applying a HIGH to the "output control" input. This allows additional shifters to be cascaded on the same output lines, or the shifter array to be connected to a common data bus.

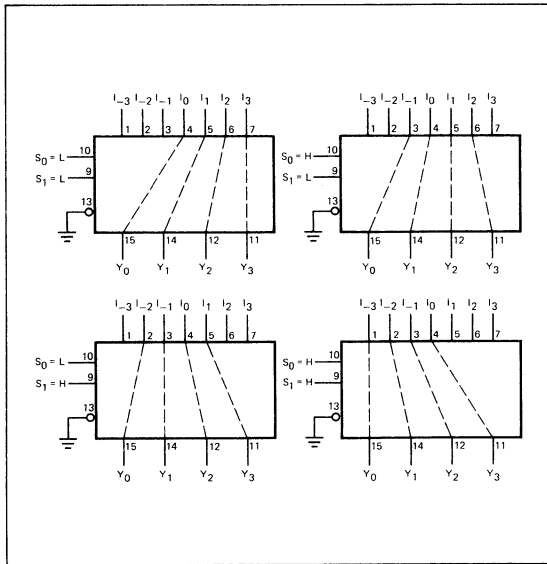


Figure 3. The Four Shift Positions of the Am25S10.

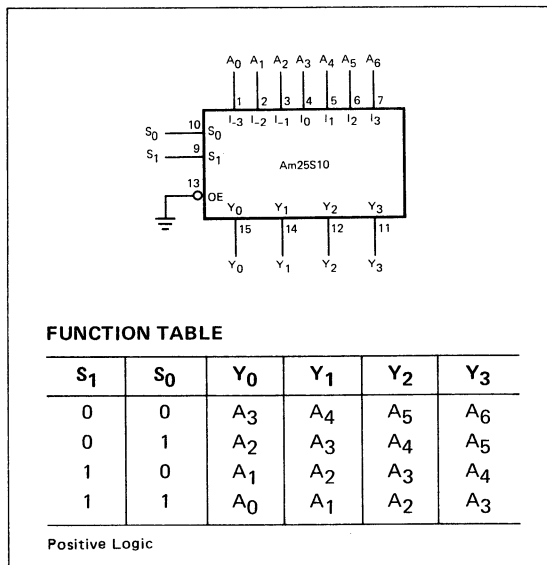


Figure 4. The Am25S10 4-Bit Shifter Operation.

INPUT LOADING

The logic diagram of Figure 2 shows the input connection scheme for the seven data inputs of the Am25S10. Table I shows the number of multiplexer inputs connected to each data input as well as the expected an actual Unit Load weighting on each input.

TABLE I

Pin #	Data Input	Number of Multiplexer Inputs Connected	Expected Unit Loads	Actual Unit Loads
1	I_{-3}	1	1	1
2	I_{-2}	2	2	1.5
3	I_{-1}	3	3	1.5
4	I_0	4	4	1.5
5	I_1	3	3	1.5
6	I_2	2	2	1.5
7	I_3	1	1	1

Since the number of gate inputs for I_{-2} , I_{-1} , I_0 , I_1 and I_2 data inputs is 2, 3, 4, 3, and 2 respectively, this could be expected to be the unit load fan-in for these data inputs. However, I_{IL} current sharing occurs internally with the select buffer outputs to reduce the external fan-in. Since a Schottky TTL unit load is defined as -2.0mA measured at 0.5V LOW , the maximum I_{IL} when measured at $V_{IL} = 0.5\text{V}$ is -3mA or 1.5 STTL unit loads. As the measure voltage V_{IL} on these data inputs is decreased to 0V , the measured input current on I_{-2} , I_{-1} , I_0 , I_1 , and I_2 can increase to an I_{IL} maximum of -4 , -6 , -8 , -6 and -4 mA respectively because of the decrease in current sharing with the internal select buffer outputs.

A plot of the typical input voltage versus input current for the data inputs is shown in Figure 5. This Figure shows the increased input current flow (negative current) as the input voltage is decreased. It also shows the effect of the input clamp diode as forward bias is applied.

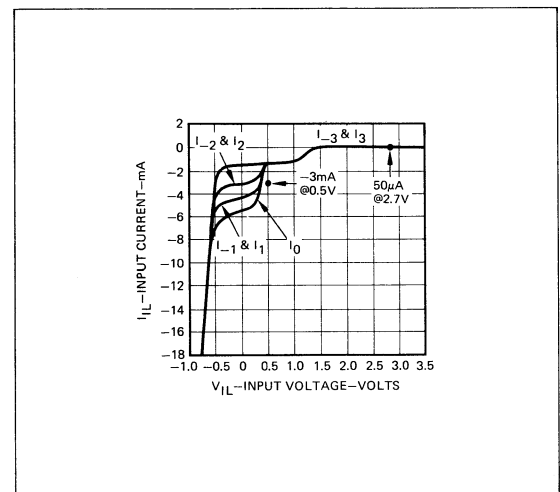


Figure 5. Typical Input Current Characteristics.

LOGIC EQUIVALENTS OF THE Am25S10

The Am25S10 exhibits several symmetrical properties that may be of advantage in some designs. These symmetrical properties involve the labeling of the inputs and outputs and the polarity of the select inputs. By relabeling the inputs in reverse order, labeling the outputs in reverse order, and considering the select inputs in positive logic (active-HIGH) or negative logic (active-LOW), eight logic equivalents for the device are possible. Figure 6 shows the operation of the device for the four combinations of input and output definitions for

the positive logic notation while Figure 7 shows the operation of the device for the four combinations for the negative logic notation. The logic symbol for each set of definitions for the input pins and output pins is shown adjacent to the truth table.

This relabeling of pins can provide the designer with some flexibility in printed circuit board layout. Likewise, the select code can be either positive logic or negative logic and the input data will be passed non-inverted. In some cases, the re-definition allows the designer to visualize shifting up versus shifting down for the same select code.

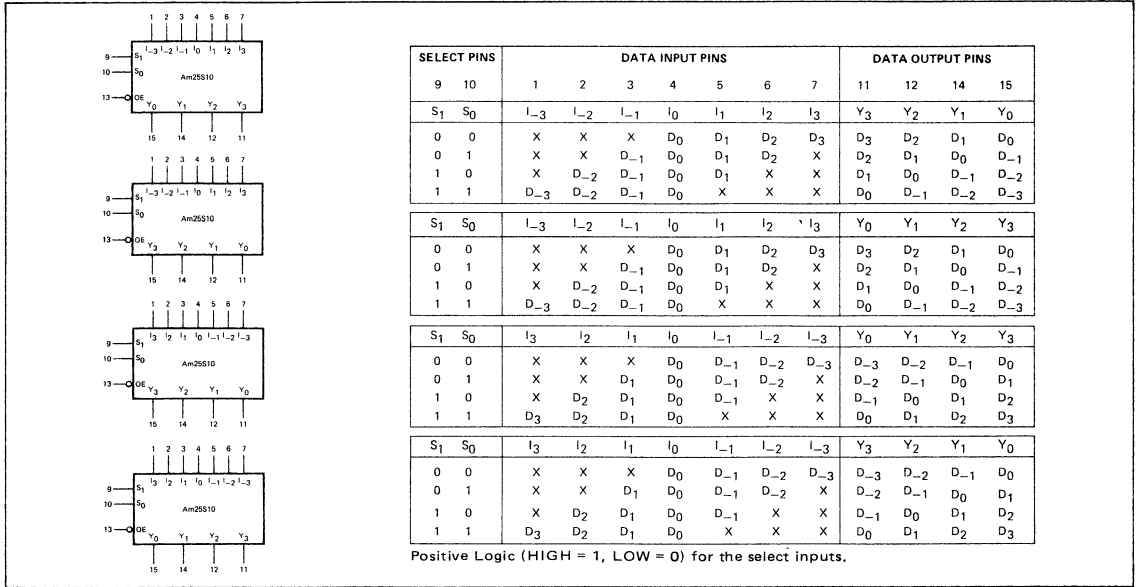


Figure 6. Four Possible Input and Output Combinations for the Positive Logic Definition.

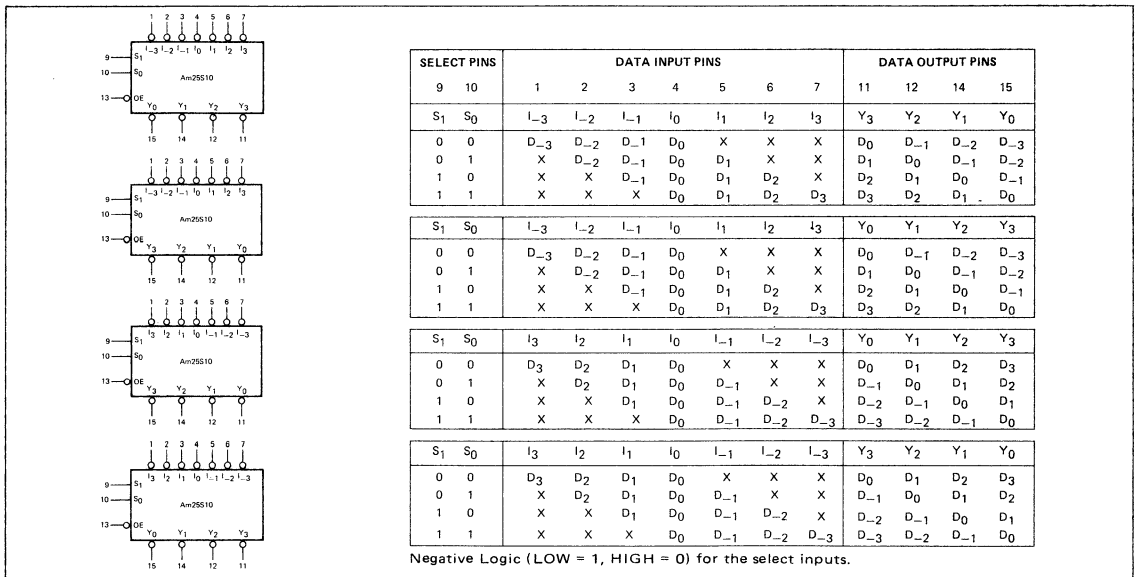


Figure 7. Four Possible Input and Output Combinations for the Negative Logic Definition.

Am25S10 APPLICATIONS

The four-bit shifter is an ideal MSI element for high-speed shifting and scaling in digital systems. By suitable inter-connection of the inputs and outputs, shifts of any number of places up or down can be made with a propagation delay of only one device. Shifting can be logical, with zeroes pulled in at either or both ends of the shifting field; arithmetic, where the sign bit is repeated during a shift down; or end around, where the data word forms a continuous loop. The three-state outputs can be used to increase the number of places shifted and also facilitate rapid data bus access in bus organized systems.

The Connection Diagram and Function Table of Figure 8 show a 16-bit word shifted up 0, 1, 2 or 3 places. In this example, the most significant bits (A_{13}, A_{14}, A_{15}) are discarded and logic zeroes are shifted in at the least significant end.

Figure 9 shows a Connection Diagram and Function Table for a 12-bit word shifted down 0, 1, 2 or 3 places. In this example, zeroes are shifted into the most significant bits and the least significant bits are discarded. Notice that one of the alternate definitions and pin assignments has been used to define the Am25S10.

A complete end-around barrel shift of 0, 1, 2, 3, 4, 5, 6 or 7 places is shown in Figure 10. In this configuration, the three-state capability of the outputs is used to connect one of two Am25S10's to the data output under the control of the S_2 and

\bar{S}_2 select inputs. This technique can be expanded for longer word lengths by using one-of-four or one-of-eight decoders to control the active-LOW "output control" input.

A 13-bit two's complement scaler is shown in Figure 11. For this connection, the sign bit is pulled in at the most significant end and the least significant bits are truncated. Thus, the 13-bit two's complement binary output number is scaled to 1, 1/2, 1/4, or 1/8 of its input value.

A two-level 16-bit barrel shifter and its associated Function Table are shown in Figure 12. Only eight Am25S10's are required to perform this function. For clarity, the intermediate level of inputs and outputs have been labeled B_i . The sixteen-bit output word can be bus connected and controlled via the \bar{OE} input.

Figure 13 demonstrates a unique way to convert a fixed point positive number to a floating-point mantisa and exponent. The priority encoder is used to determine the most significant bit position of the input word with a binary "1". The priority encoder output is a binary weighted code representing the number of places the input word is to be shifted up. This code controls the Am25S10 shifting array and shifts the input word such that the Y_7 -bit of the mantisa is always a binary one (except for $A = 0$). The exponent is of the form 2^{-n} where n is the value of the binary weighted code from the priority encoder. Thus, the output of this functional block is of the form $Y2^{-n}$.

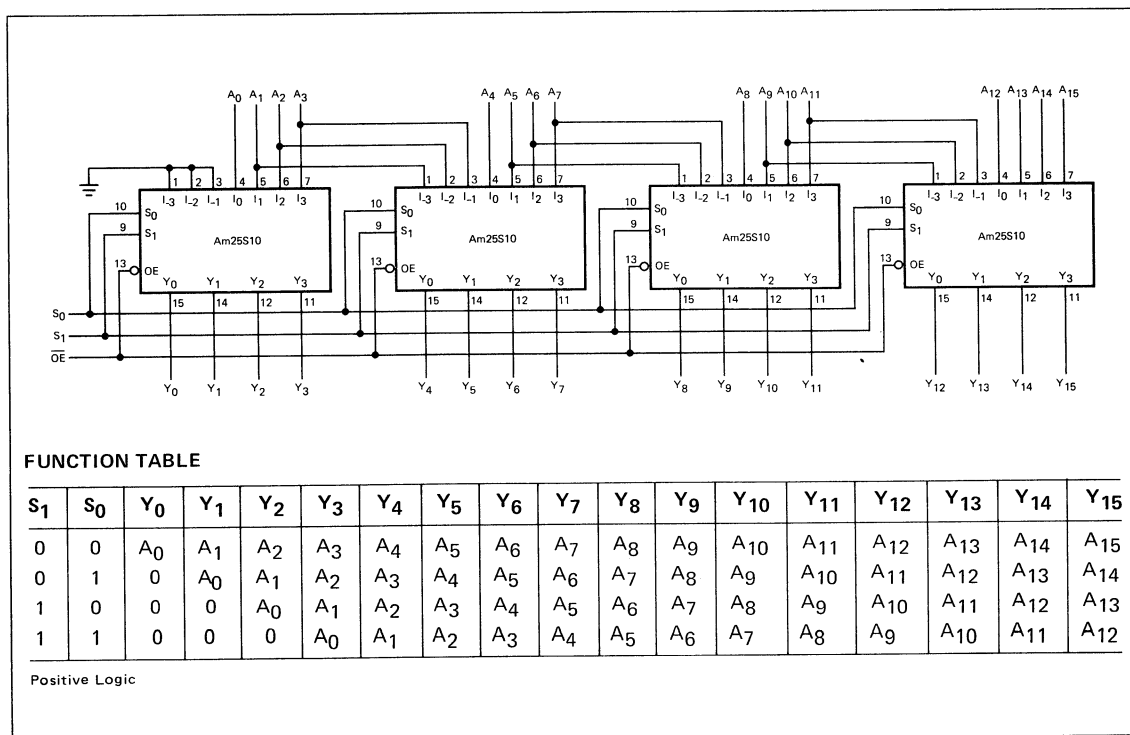
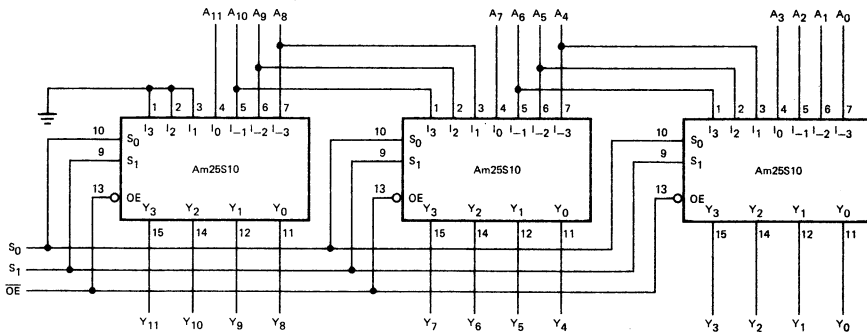


Figure 8. 16-Bit Shift-Up 0, 1, 2 or 3 Places.

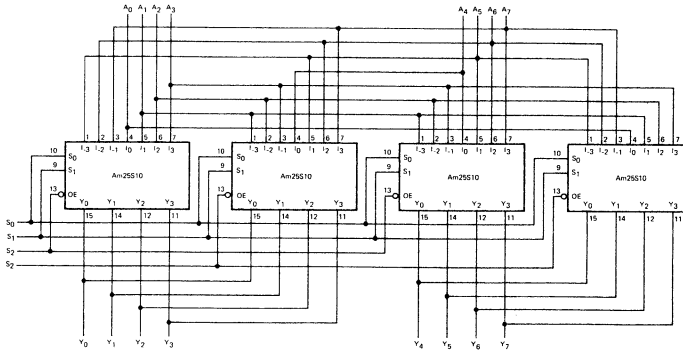


FUNCTION TABLE

S ₁	S ₀	Y ₀	Y ₁	Y ₂	Y ₃	Y ₄	Y ₅	Y ₆	Y ₇	Y ₈	Y ₉	Y ₁₀	Y ₁₁
0	0	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁
0	1	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	0
1	0	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	0	0
1	1	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	0	0	0

Positive Logic (Alternate Definitions)

Figure 9. 12-Bit Shift-Down 0, 1, 2 or 3 Places.



FUNCTION TABLE

S ₂	S ₁	S ₀	Y ₀	Y ₁	Y ₂	Y ₃	Y ₄	Y ₅	Y ₆	Y ₇
0	0	0	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇
0	0	1	A ₇	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆
0	1	0	A ₆	A ₇	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅
0	1	1	A ₅	A ₆	A ₇	A ₀	A ₁	A ₂	A ₃	A ₄
1	0	0	A ₄	A ₅	A ₆	A ₇	A ₀	A ₁	A ₂	A ₃
1	0	1	A ₃	A ₄	A ₅	A ₆	A ₇	A ₀	A ₁	A ₂
1	1	0	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₀	A ₁
1	1	1	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₀

Positive Logic

Figure 10. Eight-Bit End Around Shift 0, 1, 2, 3, 4, 5, 6 or 7 Places.

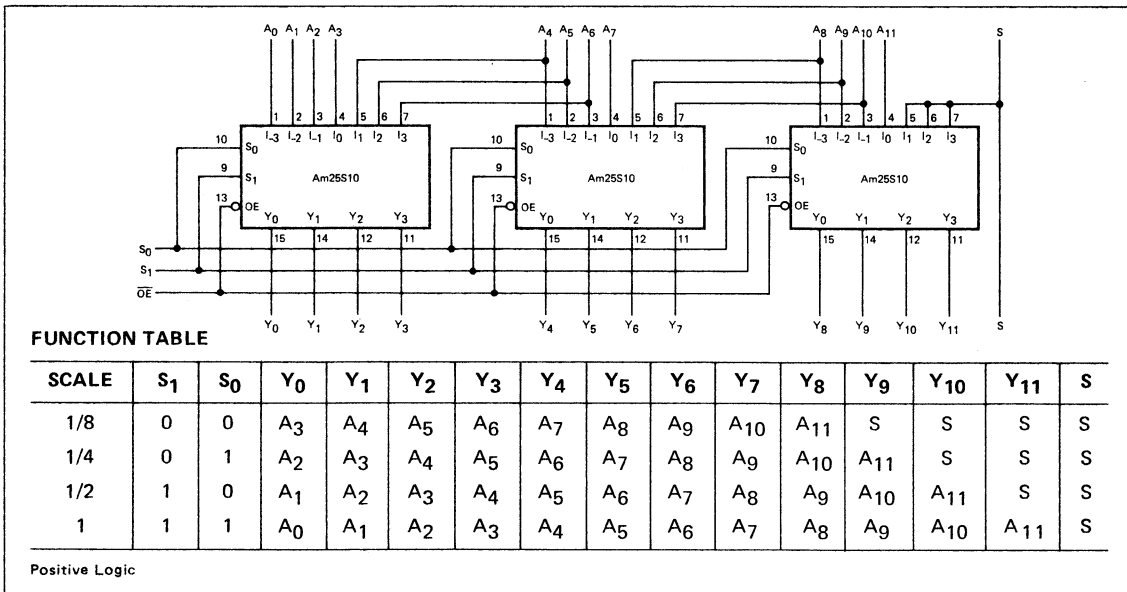


Figure 11. 13-Bit 2's Complement Scaler.

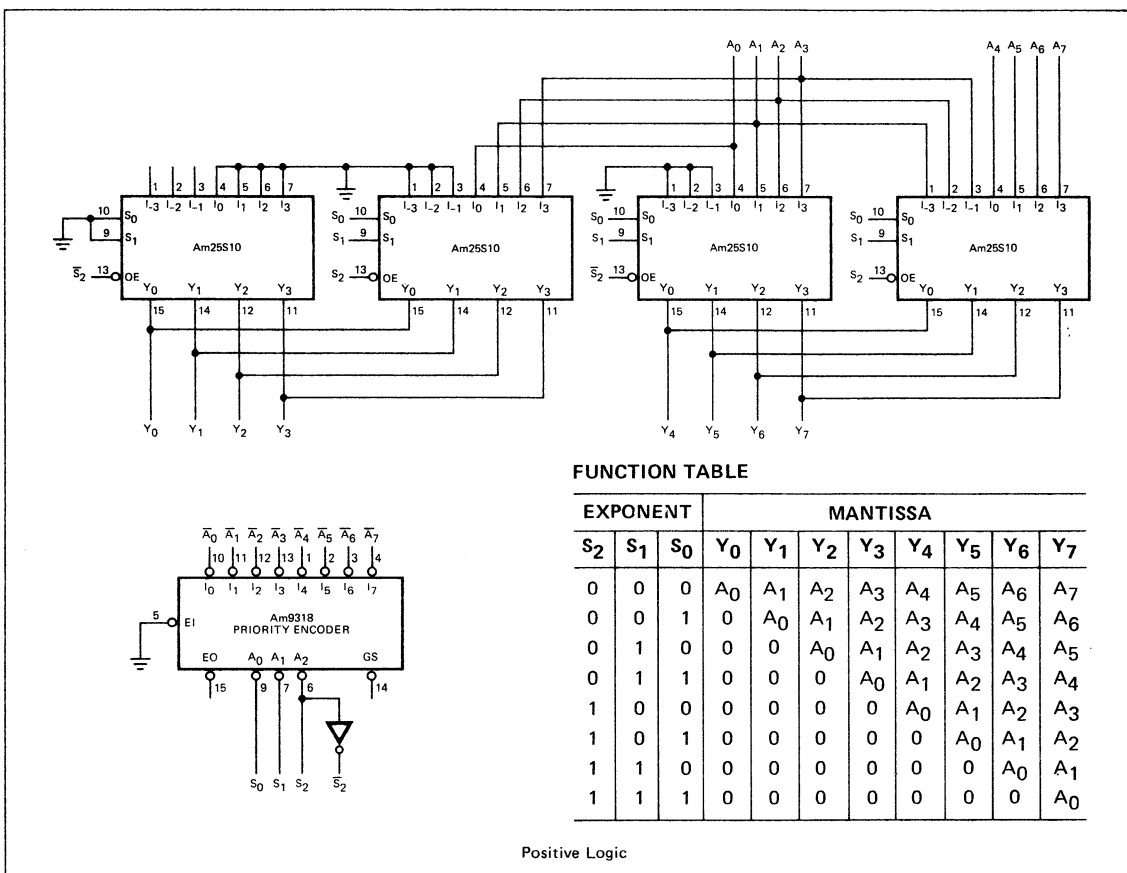
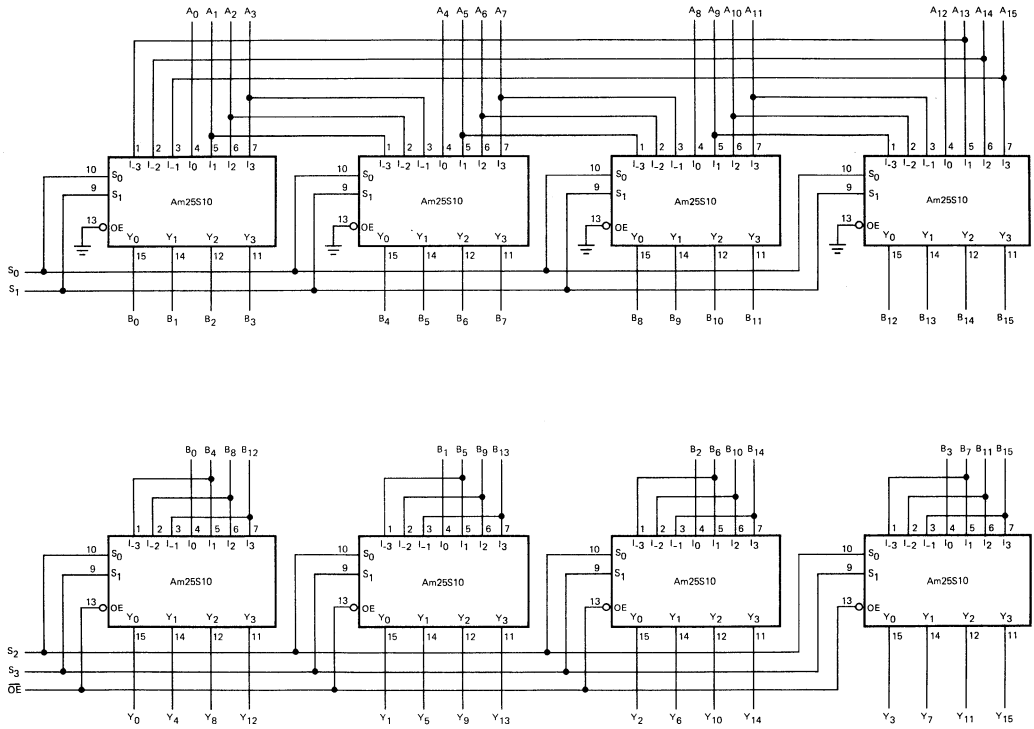


Figure 13. Binary Scaling to Give Mantissa and Exponent.

4



FUNCTION TABLE

S ₃	S ₂	S ₁	S ₀	Y ₀	Y ₁	Y ₂	Y ₃	Y ₄	Y ₅	Y ₆	Y ₇	Y ₈	Y ₉	Y ₁₀	Y ₁₁	Y ₁₂	Y ₁₃	Y ₁₄	Y ₁₅
0	0	0	0	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅
0	0	0	1	A ₁₅	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄
0	0	1	0	A ₁₄	A ₁₅	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃
0	0	1	1	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂
0	1	0	0	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁
0	1	0	1	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀
0	1	1	0	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉
0	1	1	1	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈
1	0	0	0	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇
1	0	0	1	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆
1	0	1	0	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁	A ₂	A ₃	A ₄	A ₅
1	0	1	1	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁	A ₂	A ₃	A ₄
1	1	0	0	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁	A ₂	A ₃
1	1	0	1	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁	A ₂
1	1	1	0	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀	A ₁
1	1	1	1	A ₁	A ₂	A ₃	A ₄	A ₅	A ₆	A ₇	A ₈	A ₉	A ₁₀	A ₁₁	A ₁₂	A ₁₃	A ₁₄	A ₁₅	A ₀

Positive Logic

Figure 12. Full 16-Bit Barrel Shifter.

FIXED MULTIPLIERS

Digital systems requiring multiplication by a constant integer or constant fraction can make effective use of the Am25S10 if the constant must be varied over several values. By using four-bit shifters and high-speed adders, very high-speed "constant coefficient" or fixed multipliers can be built. The technique is shown diagrammatically in Figure 14. Here, the input word C is wired to the adder A inputs such that a shift of $\frac{1}{2} C$ is "built-in". The Am25S10 shifter is wired to the B inputs of the adder such that its four select states represent pre-scaling of $\frac{1}{4} C$, $\frac{1}{8} C$, $\frac{1}{16} C$, and $\frac{1}{32} C$ of the C input word. If the \overline{OE} input is used to disable the outputs (high impedance), the adder B inputs will assume the logical one state (HIGH). By adding a "one" at the adder carry input least significant end, the contribution of the B inputs to the sum output is zero and the adder A input will be passed to the output. Thus, the \overline{OE} input can be used to generate a zero C value from the shifter.

Figure 15 shows the actual connection diagram for a 12-bit two's complement fixed multiplier using the scheme of Figure 14. The Y output weighting is the same as shown in the

Function Table of Figure 14. The \overline{OE} input is tied directly to the adder least significant C_n input to complete the shifter "zero" output function.

Figure 16 shows two shifter arrays used in conjunction with one adder. For the shifter A and shifter B select codes shown, twenty multiplication constants are realized with seventeen constants being unique. Other combinations could be used to realize different outputs. The combinations possible can be extended greatly by using multiple adders and multiple shifting arrays. For the example of Figure 16, the zero shifter output (high-impedance state) is used with only one shifter since only one C_n input is available.

This technique for fixed constant multipliers can be applied to two's complement, one's complement, sign-magnitude, or magnitude only arithmetic. In so doing, the sign must be handled appropriately and the adder output word size and number range must be considered. For the one's complement case, the all ones representation for zero must be handled separately.

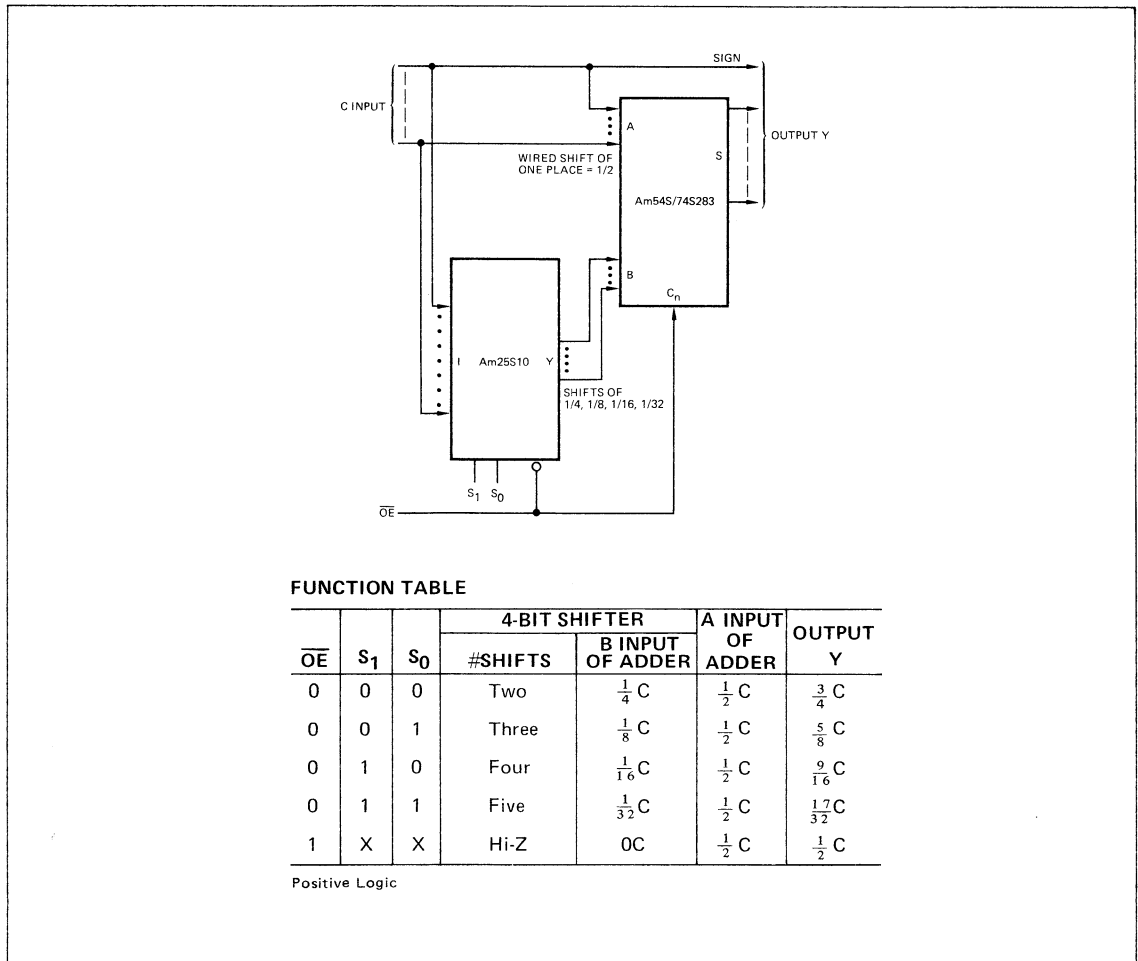


Figure 14. Parallel "Constant Coefficient" Multiplier Block Diagram and Function Table.

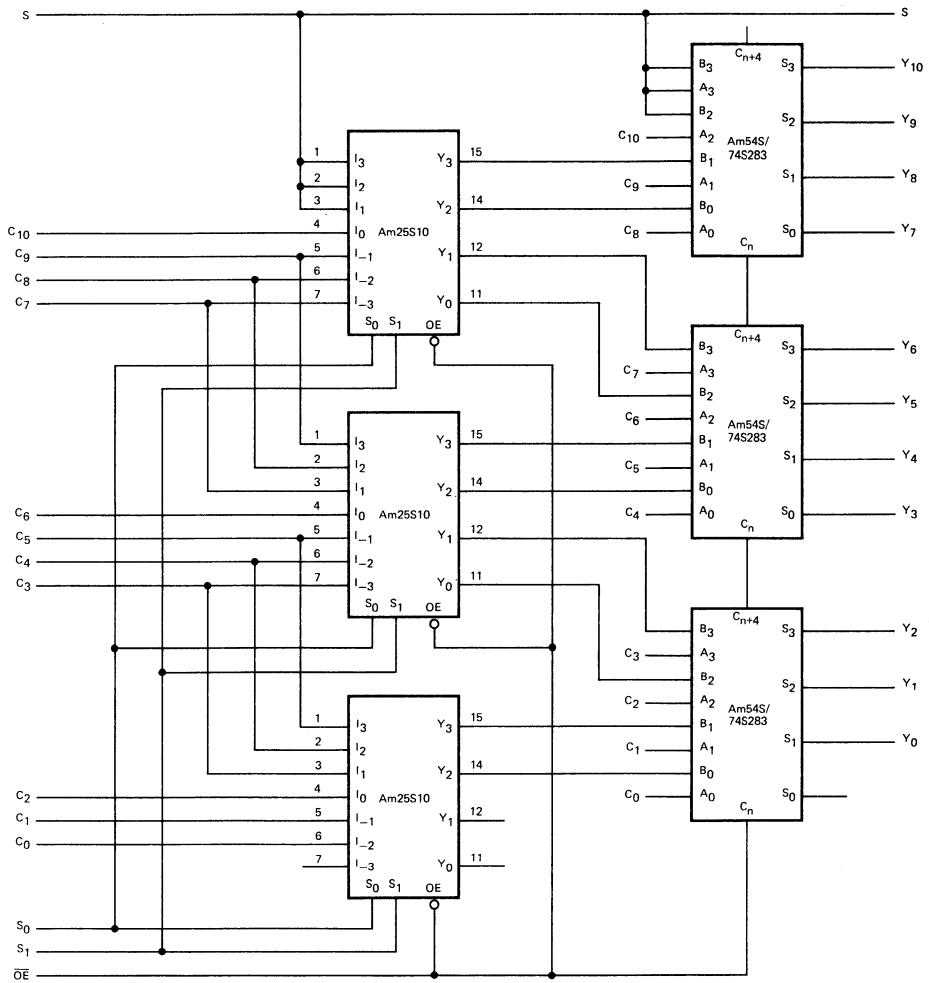
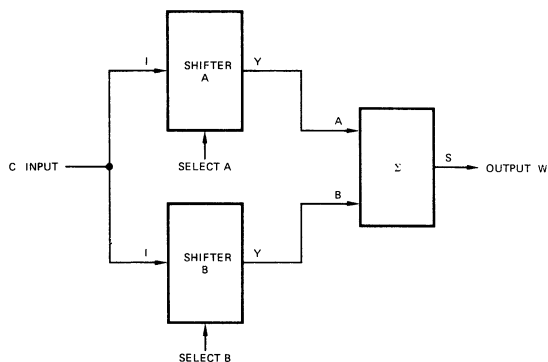


Figure 15. 12-Bit 2's Complement "Constant Coefficient" Multiplier.



$$\text{SHIFTER A} = C, \frac{C}{2}, \frac{C}{4}, \frac{C}{8}$$

$$\text{SHIFTER B} = \frac{C}{4}, \frac{C}{8}, \frac{C}{16}, \frac{C}{32}, 0$$

FIXED MULTIPLIER OUTPUT W

SHIFTER A \ SHIFTER B	SHIFTER B				
	$\frac{C}{4}$	$\frac{C}{8}$	$\frac{C}{16}$	$\frac{C}{32}$	0
C	$\frac{5}{4}C$	$\frac{9}{8}C$	$\frac{17}{16}C$	$\frac{33}{32}C$	C
$\frac{C}{2}$	$\frac{3}{4}C$	$\frac{5}{8}C$	$\frac{9}{16}C$	$\frac{17}{32}C$	$\frac{1}{2}C$
$\frac{C}{4}$	$\frac{1}{2}C$	$\frac{3}{8}C$	$\frac{5}{16}C$	$\frac{9}{32}C$	$\frac{1}{4}C$
$\frac{C}{8}$	$\frac{3}{8}C$	$\frac{1}{4}C$	$\frac{3}{16}C$	$\frac{5}{32}C$	$\frac{1}{8}C$

Figure 16. Two Shifter Arrays and One Adder Array in a Fixed Multiplier Connection.

CONCLUSION

The Am25S10 four-bit shifter is a new unique combinatorial logic element offering the system designer new shifting and scaling capability not previously available in a single package.

The three-state output design of the Am25S10 provides increased flexibility in its use and the advanced Schottky construction offers minimum propagation delay. The device can be used to shift any number of bits any number of places; up, down or end-around.

Am25S18

Quad D Register With Standard And Three-State Outputs

Distinctive Characteristics

- Advanced Schottky technology
- Four D-type flip-flops
- Four standard totem-pole outputs

- Four three-state outputs
- 75 MHz clock frequency
- 100% reliability assurance testing in compliance with MIL-STD-883

FUNCTIONAL DESCRIPTION

The Am25S18 consists of four D-type flip-flops with a buffered common clock. Information meeting the set-up and hold requirements on the D inputs is transferred to the Q outputs on the LOW-to-HIGH transition of the clock.

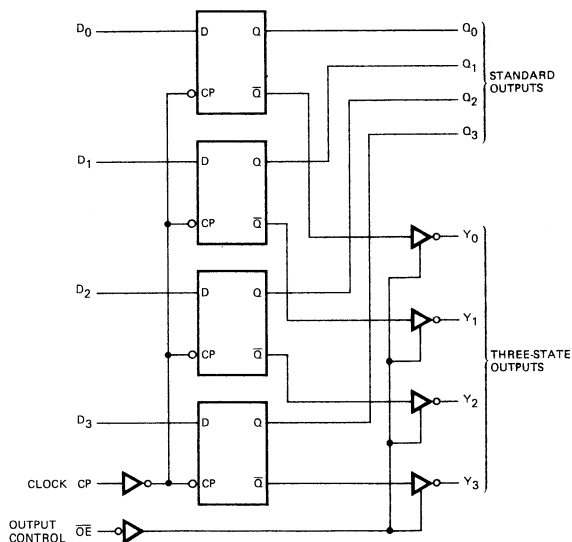
The same data as on the Q outputs is enabled at the three-state Y outputs when the "output control" (\overline{OE}) input is LOW. When the \overline{OE} input is HIGH, the Y outputs are in the high-impedance state.

The Am25S18 is a 4-bit, high speed Schottky register intended for use in real-time signal processing systems where the standard outputs are used in a recursive algorithm and the three state outputs provide access to a data bus to dump the results after a number of iterations.

The device can also be used as an address register or status register in computers or computer peripherals.

Likewise, the Am25S18 is also useful in certain display applications where the standard outputs can be decoded to drive LED's (or equivalent) and the three-state outputs are bus organized for occasional interrogation of the data as displayed.

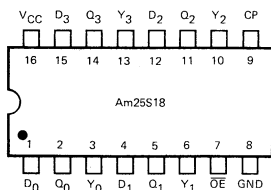
LOGIC DIAGRAM



ORDERING INFORMATION

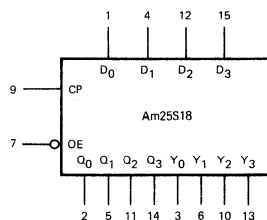
Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	AM25S18PC
Hermetic DIP	0°C to +70°C	AM25S18DC
Dice	0°C to +70°C	AM25S18XC
Hermetic DIP	-55°C to +125°C	AM25S18DM
Hermetic Flat Pak	-55°C to +125°C	AM25S18FM
Dice	-55°C to +125°C	AM25S18XM

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am25S18XC T_A = 0°C to +70°C V_{CC} = 5.0V ± 5% (COM'L) MIN. = 4.75V MAX. = 5.25V
 Am25S18XM T_A = -55°C to +125°C V_{CC} = 5.0V ± 10% (MIL) MIN. = 4.5V MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., V _{IN} = V _{IH} or V _{IL}	Q I _{OH} = -1mA	MIL 2.5	3.4	Volts
			COM'L 2.7	3.4		
		Y	XM, I _{OH} = -2mA	2.4	3.4	
			XC, I _{OH} = -6.5mA	2.4	3.2	
V _{OL}	Output LOW Voltage (Note 6)	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{IL} (Note 3)	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V			-2.0	mA
I _{IH} (Note 3)	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			50	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA
I _O	Y Output Off-State Leakage Current	V _{CC} = MAX.	V _O = 2.4V		50	μA
			V _O = 0.4V		-50	
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX.	-40		-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)		80	130	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, T_A = 25°C ambient and maximum loading.
 3. Actual input currents = Unit Load Current x Input Load Factor (see Loading Rules).
 4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 5. I_{CC} is measured with all inputs at 4.5V and all outputs open.
 6. Measured on Q outputs with Y outputs open. Measured on Y outputs with Q outputs open.



Switching Characteristics (T_A = +25°C, V_{CC} = 5.0V, R_L = 280Ω)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units		
t _{PLH}	Clock to Q Output	C _L = 15pF		6.0	9.0	ns		
t _{PHL}				8.5	13			
t _{pw}	Clock Pulse Width		HIGH	7.0		ns		
			LOW	9.0				
t _s	Data		5.0		ns			
t _h	Data		3.0		ns			
t _{PLH}	Clock to Y Output (OE LOW)	C _L = 15pF		6.0	9.0	ns		
t _{PHL}				8.5	13			
t _{ZH}	Output Control to Output		C _L = 15pF		12.5	19	ns	
t _{ZL}					12	18		
t _{HZ}				C _L = 5.0pF		4.0		6.0
t _{LZ}						7.0		10.5
f _{max}	Maximum Clock Frequency	C _L = 15pF	75	100		MHz		

TRUTH TABLE

INPUTS			OUTPUTS		NOTES
\overline{OE}	CLOCK CP	D	Q	Y	
H	L	X	NC	Z	—
H	H	X	NC	Z	—
H	↑	L	L	Z	—
H	↑	H	H	Z	—
L	↑	L	L	L	—
L	↑	H	H	H	—
L	—	—	L	L	1
L	—	—	H	H	1

L = LOW
H = HIGH
X = Don't care
NC = No change
↑ = LOW to HIGH transition
Z = High impedance

Note: 1. When \overline{OE} is LOW, the Y output will be in the same logic state as the Q output.

DEFINITION OF FUNCTIONAL TERMS

D_i The four data inputs to the register.

Q_i The four data outputs of the register with standard totem-pole active pull-up outputs. Data is passed non-inverted.

Y_i The four three-state data outputs of the register. When the three-state outputs are enabled, data is passed non-inverted. A HIGH on the "output control" input forces the Y_i outputs to the high-impedance state.

CP Clock. The buffered common clock for the register. Enters data on the LOW-to-HIGH transition.

\overline{OE} Output Control. When the \overline{OE} input is HIGH, the Y_i outputs are in the high-impedance state. When the \overline{OE} input is LOW, the TRUE register data is present at the Y_i outputs.

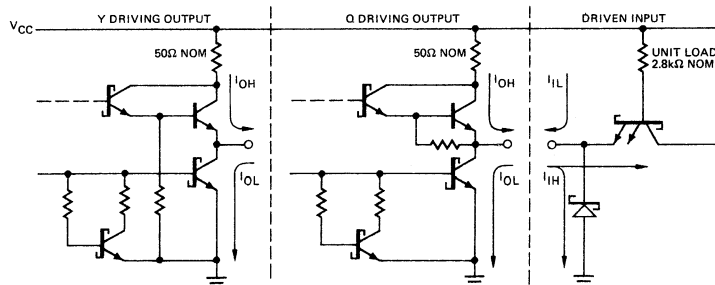
LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
D ₀	1	1	—	—
Q ₀	2	—	20	10*
Y ₀	3	—	40/130	10*
D ₁	4	1	—	—
Q ₁	5	—	20	10*
Y ₁	6	—	40/130	10*
\overline{OE}	7	1	—	—
GND	8	—	—	—
CP	9	1	—	—
Y ₂	10	—	40/130	10*
Q ₂	11	—	20	10*
D ₂	12	1	—	—
Y ₃	13	—	40/130	10*
Q ₃	14	—	20	10*
D ₃	15	1	—	—
V _{CC}	16	—	—	—

A Schottky TTL Unit Load is defined as 50μA measured at 2.7V HIGH and -2.0mA measured at 0.5V LOW.

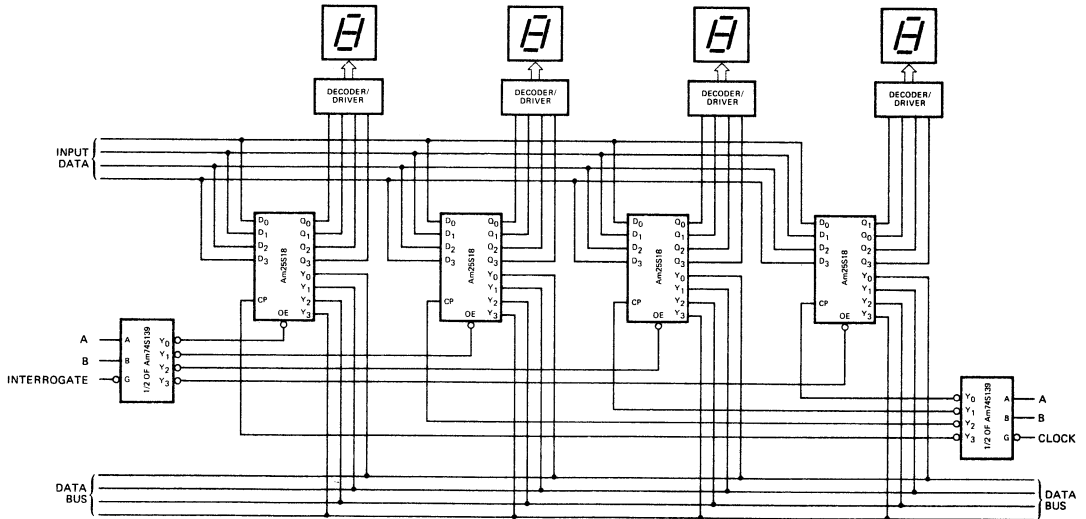
*Fan-out on each Q_i and Y_i output pair should not exceed 15 unit loads (30mA) for i = 0, 1, 2, 3.

SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS

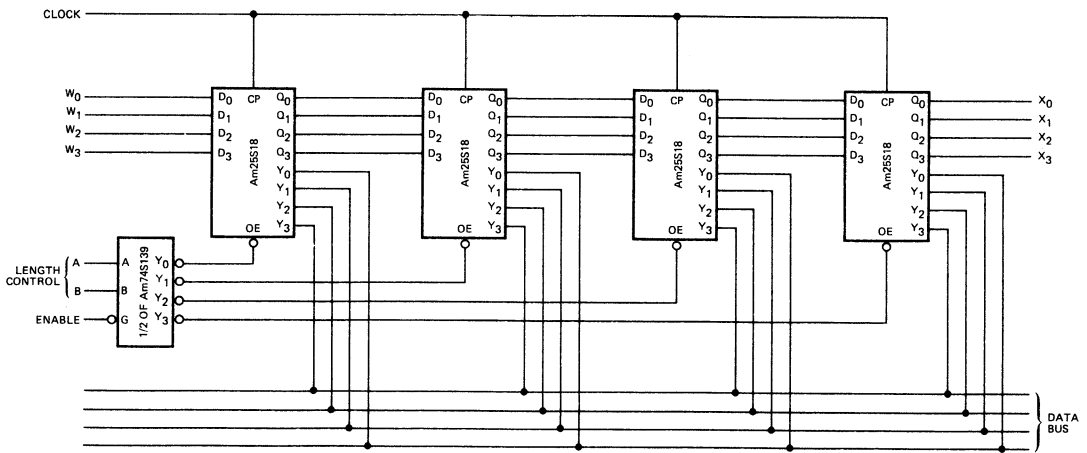


Note: Actual current flow direction shown.

APPLICATIONS

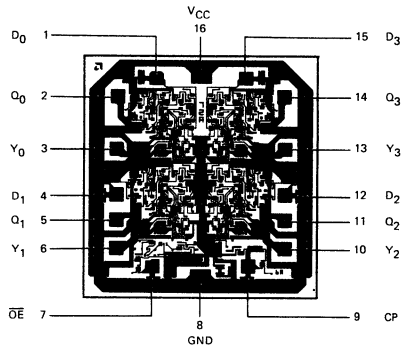


THE Am25S18 USED AS DISPLAY REGISTER WITH BUS INTERROGATE CAPABILITY.



THE Am25S18 AS A VARIABLE LENGTH (1, 2, 3 or 4 WORD) SHIFT REGISTER.

Metallization and Pad Layout



DIE SIZE
0.077" X 0.079"

4

Am26S02

Schottky Dual Retriggerable, Resettable Monostable Multivibrator

Distinctive Characteristics

- Advanced Schottky technology with PNP inputs
- Retriggerable 0% to 100% duty cycle
- 28ns to ∞ output pulse width range
- 100k Ω maximum timing resistor value
- Am26S02XM typical pulse width change of only 1.0% over -55°C to $+125^{\circ}\text{C}$ with $R_X = 100\text{k}\Omega$.
- Am26S02XC typical pulse width change of only 0.4% over 0°C to $+70^{\circ}\text{C}$ with $R_X = 100\text{k}\Omega$

FUNCTIONAL DESCRIPTION

The Am26S02 is a dual DC level sensitive, retriggerable, resettable monostable multivibrator built using advanced Schottky technology. The output pulse duration and accuracy depend on the external timing components of each multivibrator. The Am26S02 features PNP inputs to reduce the input loading.

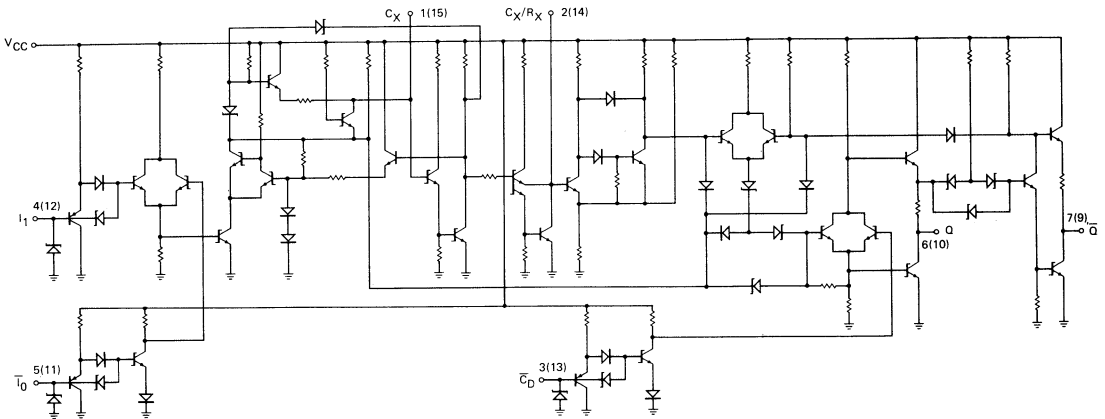
Provision is made on each multivibrator circuit for triggering the PNP inputs on either the rising or falling edge of an input signal by including an inverting and non-inverting trigger input. These PNP inputs are DC coupled making triggering independent of the input rise or fall time. Each time the monostable trigger input is activated from the OR

trigger gate, full pulse length triggering occurs independent of the present state of the monostable.

The direct clear PNP input allows a timing cycle to be terminated at any time during the cycle. A LOW on the clear input forces the Q output LOW regardless of the \bar{I}_0 or \bar{I}_1 inputs.

The Am26S02XM has a typical pulse width change of only 1.0% over the full military -55°C to $+125^{\circ}\text{C}$ temperature range and the Am26S02XC has a typical pulse width change of only 0.4% over the commercial 0°C to $+70^{\circ}\text{C}$ temperature range with a $R_X = 100\text{k}\Omega$.

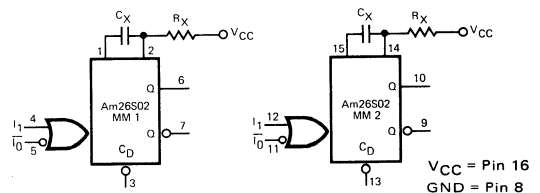
SCHEMATIC DIAGRAM (One Monostable Multivibrator Shown)



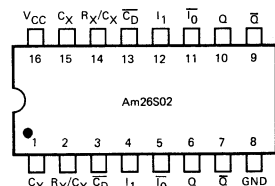
ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to $+70^{\circ}\text{C}$	AM26S02PC
Hermetic DIP	0°C to $+70^{\circ}\text{C}$	AM26S02DC
Dice	0°C to $+70^{\circ}\text{C}$	AM26S02XC
Hermetic DIP	-55°C to $+125^{\circ}\text{C}$	AM26S02DM
Hermetic Flat Pak	-55°C to $+125^{\circ}\text{C}$	AM26S02FM
Dice	-55°C to $+125^{\circ}\text{C}$	AM26S02XM

LOGIC SYMBOLS



CONNECTION DIAGRAM



Note:
Pin 1 is marked for orientation.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 V to +7 V
DC Voltage Applied to Outputs for HIGH Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +5.5 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am26S02XC	T _A = 0°C to +70°C	V _{CC} = 5.0 V ±5% (COM'L)	MIN. = 4.75 V	MAX. = 5.25 V
Am26S02XM	T _A = -55°C to +125°C	V _{CC} = 5.0 V ±10% (MIL)	MIN. = 4.5 V	MAX. = 5.5 V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ.(Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -2mA V _{IN} = V _{IH} or V _{IL}	2.5	2.8		Volts
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}		0.38	0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA		-0.8	-1.2	Volts
I _{IL} (Note 3)	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V		-0.15	-0.4	mA
I _{IH} (Note 3)	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V		0.1	20	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 1.0V T _A = 25°C Only	-8	-15	-35	mA
I _{CC}	Power Supply Current	V _{CC} = 5.0 V, I _I X = 0.33 mA (Notes 5&6)		48	69	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0 V, 25°C ambient and maximum loading.
 3. Actual input currents = Unit Load x Input Load Factor (See Loading Rules).
 4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 5. I_{CC} is measured with pin 5 and 11 grounded and I_IX applied to pins 2 and 14.
 6. I_IX is the current into the R_XC_X node to simulate R_X.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units	
t _{PLH}	$\overline{I_0}$ to Q	V _{CC} = 5.0 V, R _L = 280 Ω, C _L = 15 pF, R _X = 5kΩ, C _X = 0 pF		13	20	ns	
t _{PHL}	$\overline{I_0}$ to \overline{Q}			15	23	ns	
t _{PLH}	I ₁ to Q			12	20	ns	
t _{PHL}	I ₁ to \overline{Q}			12	20	ns	
t _{PLH}	Clear to \overline{Q}			21		ns	
t _{PHL}	Clear to Q			9	13	ns	
t _{pw}	Pulse Width		$\overline{I_0}$ HIGH or I ₁ LOW	20	10		ns
			$\overline{I_0}$ LOW or I ₁ HIGH	16	7		ns
			Clear LOW	24	16		ns
t _s	Clear Recovery (inactive) to Trigger			-10	-22		ns
t _{pwQ} (Min.)	Minimum Pulse Width Q Output	V _{CC} = 5.0 V, R _X = 5.0 kΩ, C _X = 0 pF R _L = 1.0 kΩ	27	33	39	ns	
t _{pwQ}	Pulse Width Q Output	V _{CC} = 5.0 V, R _L = 280 Ω, C _L = 15 pF R _X = 10 kΩ, C _X = 1000 pF (CK05 Type)	2.89	3.04	3.19	μs	
R _X	Timing Resistor	0°C to 70°C	5		100	kΩ	
		-55°C to +125°C	5		50		

DEFINITION OF FUNCTIONAL TERMS:

- \overline{C}_D Asynchronous direct CLEAR. A LOW on the clear input resets the monostable regardless of the other inputs.
- \overline{I}_0 Active-LOW input. With I_1 LOW, a HIGH-to-LOW transition will trigger the monostable.
- I_1 Active-HIGH input. With \overline{I}_0 HIGH, a LOW-to-HIGH transition will trigger the monostable.
- Q The TRUE monostable output.
- \overline{Q} The Complement monostable output.

FUNCTION TABLE

INPUTS			OUTPUTS	
\overline{C}_D	I_1	\overline{I}_0	Q	\overline{Q}
L	X	X	L	H
H	H	X	L	H
H	L	↓	⌋	⌋
H	X	L	L	H
H	↑	H	⌋	⌋

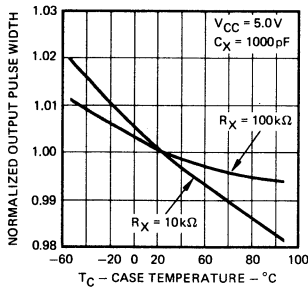
- H = HIGH
- L = LOW
- ↑ = LOW-to-HIGH Transition
- ↓ = HIGH-to-LOW Transition
- ⌋ = LOW-HIGH-LOW Pulse
- ⌋ = HIGH-LOW-HIGH Pulse
- X = Don't Care

LOADING RULES (In Unit Loads)

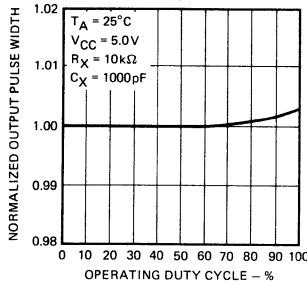
Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
C_X	Mono 1 1	—	—	—
R_X/C_X	2	—	—	—
\overline{C}_D	3	0.4	—	—
I_1	4	0.4	—	—
\overline{I}_0	5	0.4	—	—
Q	6	—	40	10
\overline{Q}	7	—	40	10
GND	8	—	—	—
\overline{Q}	Mono 2 9	—	40	10
Q	10	—	40	10
\overline{I}_0	11	0.4	—	—
I_1	12	0.4	—	—
\overline{C}_D	13	0.4	—	—
R_X/C_X	14	—	—	—
C_X	15	—	—	—
V_{CC}	16	—	—	—

A Schottky TTL Unit Load is defined as 50μA measured at 2.7V HIGH and -2.0mA measured at 0.5V LOW.

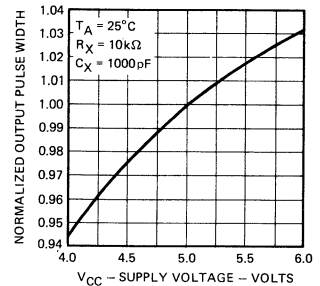
Typical Normalized Output Pulse Width Versus Case Temperature



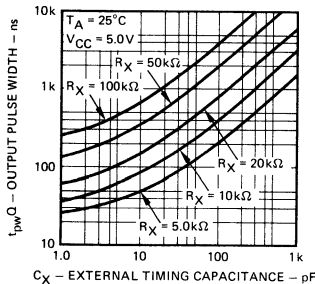
Normalized Output Pulse Width Versus Operating Duty Cycle



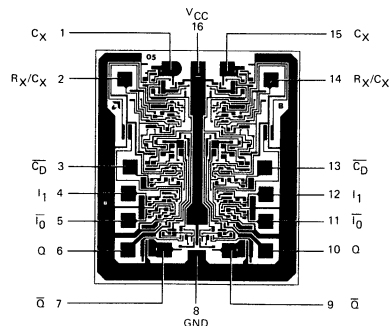
Typical Normalized Output Pulse Width Versus Supply Voltage



Output Pulse Width Versus External Timing Capacitance



Metallization and Pad Layout



DIE SIZE 0.062" X 0.071"

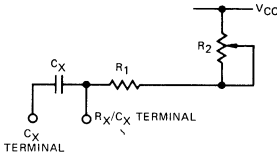
OPERATION RULES

TIMING

1. Timing components C_X and R_X values.

Operating Temperature Range		
	0°C to 70°C	-55°C to +125°C
R_X MIN.	5kΩ	5kΩ
R_X MAX.	100kΩ	50kΩ
C_X	any value	any value

2. Remote adjustment of timing.



$$R_1 + R_2 = R_X$$

$$R_1 \geq R_X \text{ MIN.}$$

$$R_2 < R_X \text{ MAX.} - R_1$$

In the above arrangement, R_1 and C_X should be as close as possible to the device pins to minimize stray capacitance and external noise pickup. The variable resistor R_2 can be located remotely from the device if reasonable care is used.

3. Pulse width change measurements.

The pulse width t_{pwQ} is specified and measured with components of better than 0.1% accuracy. If measurements are made with reduced component tolerances, the expected accuracy should be adjusted accordingly. Note that pulse width temperature stability improves as R_X increases.

4. Timing for $C_X \leq 1000$ pF.

When using capacitor of less than or equal to 1000 pF in value, the output pulse width should be determined from the output pulse width versus external timing capacitance graph.

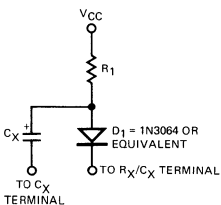
5. Timing for $C_X > 1000$ pF.

For capacitors of greater than 1000 pF in value, the output pulse width, t_{pwQ} , is determined by

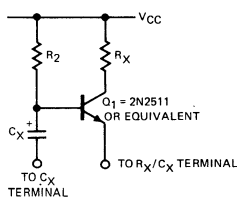
$$t_{pwQ} = 0.30 C_X R_X \left(1 + \frac{0.11}{R_X} \right)$$

where

- R_X is in kilohms
- C_X is in picofarads
- t_{pwQ} is in nanoseconds



$$R_1 \leq 0.6 \times R_X \text{ MAX.}$$



$$R_2 < 0.7 \times h_{FEQ1} \times R_X$$

6. Protection of electrolytic timing capacitors.

If the electrolytic capacitor to be used as C_X cannot withstand 1.0 volt reverse bias, one of the two circuit techniques shown below should be used to protect the electrolytic capacitor from the reverse voltage. The accuracy of the pulse width may be dependent on the diode (transistor) characteristics.

The output pulse width, t_{pwQ} for the diode circuit modifies the previous timing equation as follows:

$$t_{pwQ} = 0.26 C_X R_X \left(1 + \frac{0.13}{R_X} \right)$$

The output pulse width for the transistor circuit is

$$t_{pwQ} = 0.21 C_X R_X \left(1 + \frac{0.16}{R_X} \right)$$

Notice that the transistor circuit allows values of timing resistor R_2 larger than the R_X MIN. $< R_X < R_X$ MAX. to obtain longer output pulse widths for a given C_X .

TRIGGER AND RETRIGGER

1. Triggering.

The minimum pulse width signal into input \bar{I}_0 or input I_1 to cause the device to trigger is 20ns. Refer to the truth table for the appropriate input conditions.

2. Retriggering.

The retriggered pulse width, t_{pwrQ} , is the time during which the output is active after the device is retriggered during a timing cycle. It differs from the initial pulse width t_{pwQ} timing equation as follows.

$$t_{pwrQ} = t_{pwQ} + t_{PLH}$$

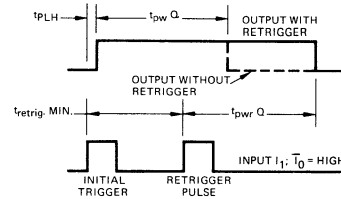
where t_{PLH} is the propagation delay time from the \bar{I}_0 or I_1 input to the output. Note that t_{PLH} is typically 14ns and therefore becomes relatively unimportant as t_{pwQ} increases.

3. Rapid retriggering.

A minimum retriggering time does exist. That is, the device cannot be retriggered until a minimum recovery time has elapsed. The minimum retrigger time is approximately.

$$t_{retrig \text{ MIN.}} = 0.2 C_X$$

C is in picofarads
t is in nanoseconds



CLEAR

A LOW on the clear inputs terminates the timing cycle. A new trigger cycle cannot be initiated while the clear is LOW. With the clear HIGH, the device is under the command of the I_1 and \bar{I}_0 inputs.

Am26S10 • Am26S11

Quad Bus Transceivers

Distinctive Characteristics

- Input to bus is inverting on Am26S10
- Input to bus is non-inverting on Am26S11
- Quad high-speed open collector bus transceivers
- Driver outputs can sink 100mA at 0.8V maximum

- Bus compatible with Am2905, Am2906, Am2907
- Advanced Schottky processing
- PNP inputs to reduce input loading
- 100% reliability assurance testing in compliance with MIL-STD-883

FUNCTIONAL DESCRIPTION

The Am26S10 and Am26S11 are quad Bus Transceivers consisting of four high-speed bus drivers with open-collector outputs capable of sinking 100mA at 0.8 volts and four high-speed bus receivers. Each driver output is connected internally to the high-speed bus receiver in addition to being connected to the package pin. The receiver has a Schottky TTL output capable of driving ten Schottky TTL unit loads.

An active LOW enable gate controls the four drivers so that outputs of different device drivers can be connected together for party-line operation. The enable input can be conveniently driven by active LOW decoders such as the Am25LS139.

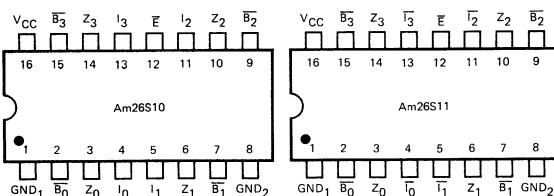
The bus output high-drive capability in the LOW state allows party-line operation with a line impedance as low as 100Ω. The line can be terminated at both ends, and still give considerable noise margin at the receiver. The receiver typical switching point is 2.0 volts.

The Am26S10 and Am26S11 feature advanced Schottky processing to minimize propagation delay. The device package also has two ground pins to improve ground current handling and allow close decoupling between V_{CC} and ground at the package. Both GND₁ and GND₂ should be tied to the ground bus external to the device package.

ORDERING INFORMATION

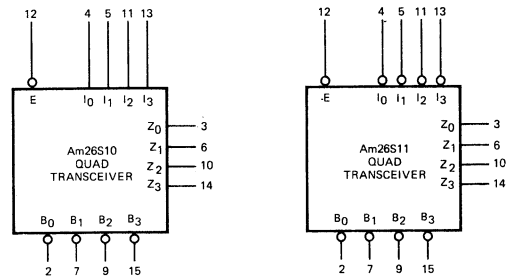
Package Type	Temperature Range	Am26S10 Order Number	Am26S11 Order Number
Molded DIP	0°C to +70°C	AM26S10PC	AM26S11PC
Hermetic DIP	0°C to +70°C	AM26S10DC	AM26S11DC
Dice	0°C to +70°C	AM26S10XC	AM26S11XC
Hermetic DIP	-55°C to +125°C	AM26S10DM	AM26S11DM
Hermetic Flat Pack	-55°C to +125°C	AM26S10FM	AM26S11FM
Dice	-55°C to +125°C	AM26S10XM	AM26S11XM

CONNECTION DIAGRAMS Top Views



Note: Pin 1 is marked for orientation.

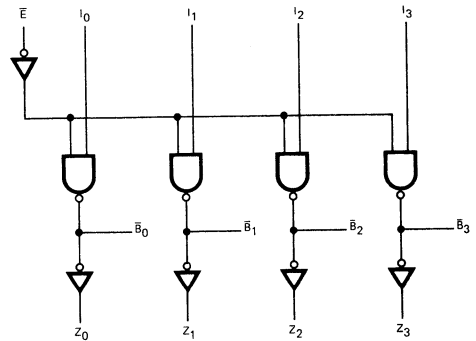
LOGIC SYMBOLS



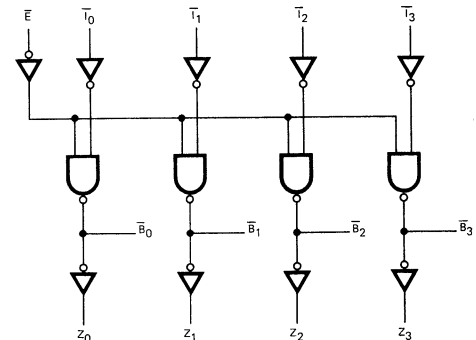
V_{CC} = Pin 16
GND₁ = Pin 1
GND₂ = Pin 8

LOGIC DIAGRAMS

Am26S10



Am26S11



MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential	-0.5V to +7V
DC Voltage Applied to Outputs for High Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
Output Current, Into Bus	200 mA
Output Current, Into Outputs (Except Bus)	30 mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE (Unless Otherwise Noted)

Am26S10XC, Am26S11XC	T _A = 0°C to +70°C	V _{CC} = 5.0 V ± 5% (COM'L)	MIN. = 4.75V	MAX. = 5.25V
Am26S10XM, Am26S11XM	T _A = -55°C to +125°C	V _{CC} = 5.0 V ± 10% (MIL)	MIN. = 4.5V	MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage (Receiver Outputs)	V _{CC} = MIN., I _{OH} = -1.0mA V _{IN} = V _{IL} or V _{IH}	MIL	2.5	3.4	Volts
			COM'L	2.7	3.4	
V _{OL}	Output LOW Voltage (Receiver Outputs)	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IL} or V _{IH}			0.5	Volts
V _{IH}	Input HIGH Level (Except Bus)	Guaranteed input logical HIGH for all inputs	2.0			Volts
V _{IL}	Input LOW Level (Except Bus)	Guaranteed input logical LOW for all inputs			0.8	Volts
V _I	Input Clamp Voltage (Except Bus)	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{IL}	Input LOW Current (Except Bus)	V _{CC} = MAX., V _{IN} = 0.4V	Enable		-0.36	mA
			Data		-0.54	
I _{IH}	Input HIGH Current (Except Bus)	V _{CC} = MAX., V _{IN} = 2.7V	Enable		20	μA
			Data		30	
I _I	Input HIGH Current (Except Bus)	V _{CC} = MAX., V _{IN} = 5.5V			100	μA
I _{SC}	Output Short Circuit Current (Except Bus)	V _{CC} = MAX. (Note 3)	MIL	-20	-55	mA
			COM'L	-18	-60	
I _{CCL}	Power Supply Current (All Bus Outputs LOW)	V _{CC} = MAX. Enable = GND	Am26S10	45	70	mA
			Am26S11		80	

Bus Input/Output Characteristics

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V _{OL}	Output LOW Voltage	V _{CC} = MIN.	MIL	I _{OL} = 40mA	0.33	0.5	Volts
				I _{OL} = 70mA	0.42	0.7	
				I _{OL} = 100mA	0.51	0.8	
			COM'L	I _{OL} = 40mA	0.33	0.5	
				I _{OL} = 70mA	0.42	0.7	
				I _{OL} = 100mA	0.51	0.8	
I _O	Bus Leakage Current	V _{CC} = MAX.	MIL	V _O = 0.8V		-50	μA
				V _O = 4.5V		200	
				V _O = 4.5V		100	
I _{OFF}	Bus Leakage Current (Power Off)	V _O = 4.5V			100	μA	
V _{TH}	Receiver Input HIGH Threshold	Bus Enable = 2.4V V _{CC} = MAX	MIL	2.4	2.0	Volts	
			COM'L	2.25	2.0		
V _{TL}	Receiver Input LOW Threshold	Bus Enable = 2.4V V _{CC} = MIN	MIL		2.0	1.6	Volts
			COM'L		2.0	1.75	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0 V, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

Switching Characteristics ($T_A = +25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units	
t_{PLH}	Data Input to Bus	$R_B = 50\Omega$ $C_B = 50\text{pF}$ (Note 1)		10	15	ns	
t_{PHL}				10	15		
t_{PLH}			Am26S11		12		19
t_{PHL}					12		19
t_{PLH}	Enable Input to Bus		Am26S10		14	18	ns
t_{PHL}					13	18	
t_{PLH}			Am26S11		15	20	
t_{PHL}					14	20	
t_{PLH}	Bus to Receiver Out	$R_B = 50\Omega$, $R_L = 280\Omega$		10	15	ns	
t_{PHL}		$C_B = 50\text{pF}$ (Note 1), $C_L = 15\text{pF}$		10	15		
t_r	Bus	$R_B = 50\Omega$	4.0	10		ns	
t_f	Bus	$C_B = 50\text{pF}$ (Note 1)	2.0	4.0		ns	

Note 1. Includes probe and jig capacitance.

TRUTH TABLES

Am26S10

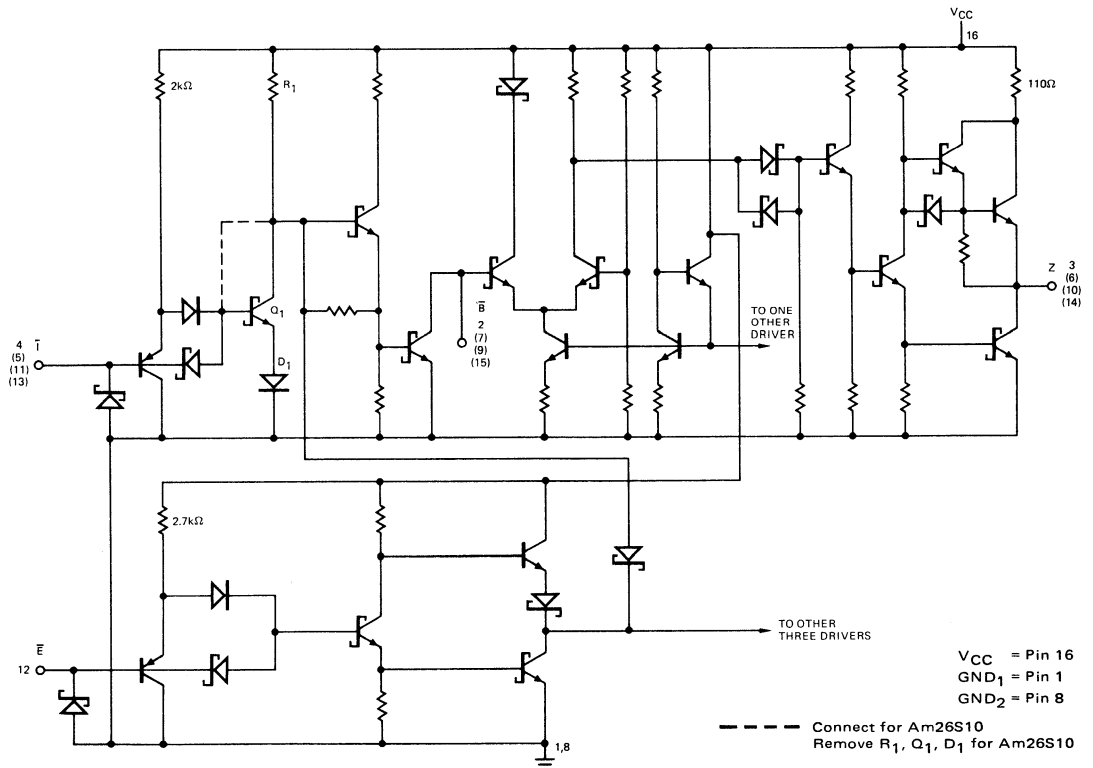
Inputs		Outputs	
\bar{E}	I	\bar{B}	Z
L	L	H	L
L	H	L	H
H	X	Y	\bar{Y}

Am26S11

Inputs		Outputs	
\bar{E}	\bar{I}	\bar{B}	Z
L	L	L	H
L	H	H	L
H	X	Y	\bar{Y}

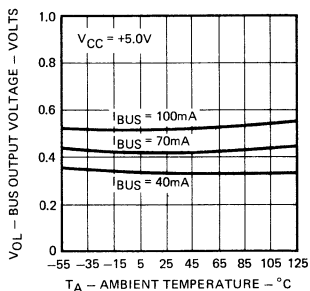
H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Don't Care
 Y = Voltage Level of Bus (Assumes Control by Another Bus Transceiver)

Am26S10/Am26S11 SCHEMATIC DIAGRAM

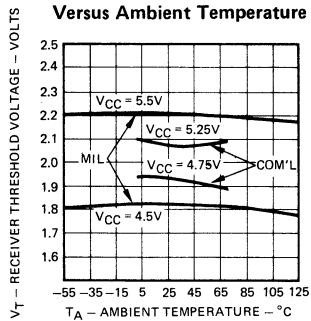


TYPICAL PERFORMANCE CURVES

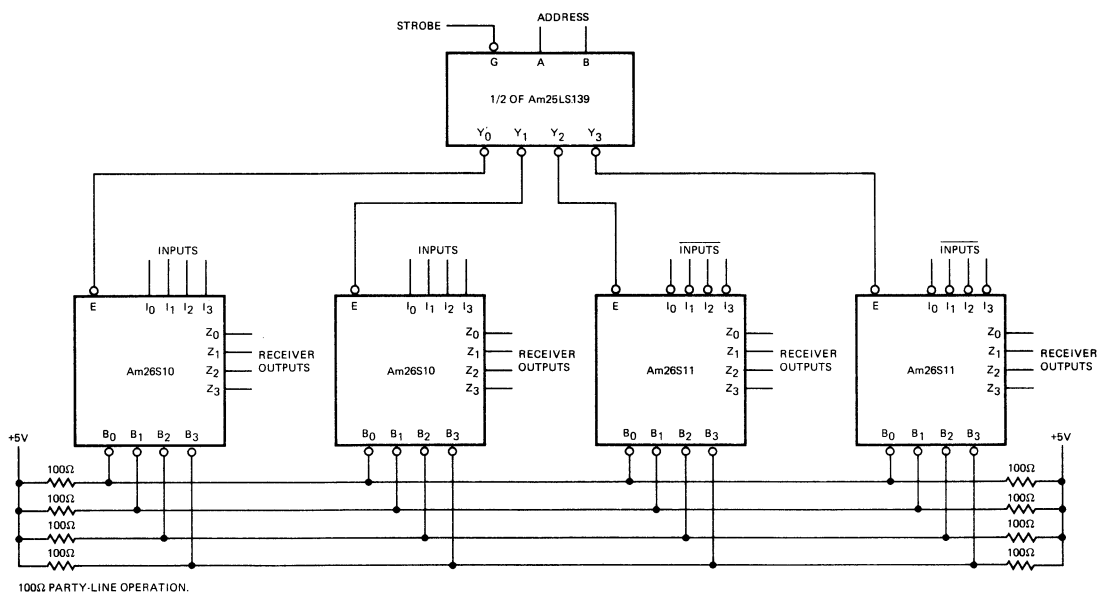
Typical Bus Output Low Voltage Versus Ambient Temperature



Receiver Threshold Variation Versus Ambient Temperature

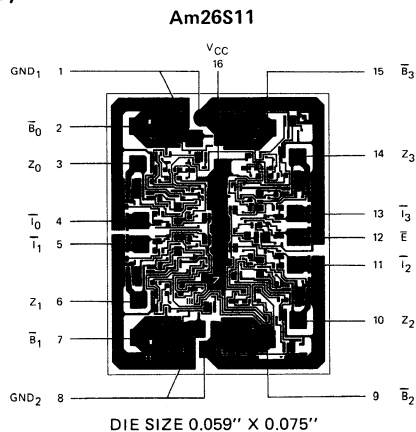
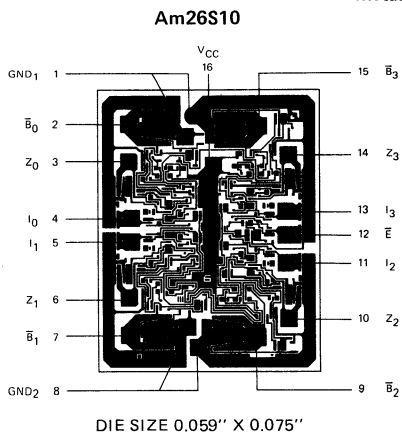


TYPICAL APPLICATION



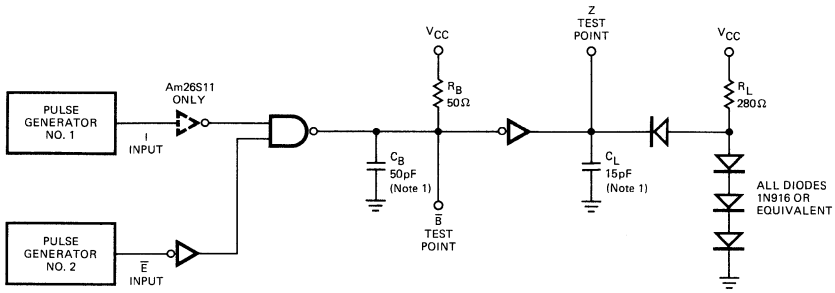
4

Metallization and Pad Layout



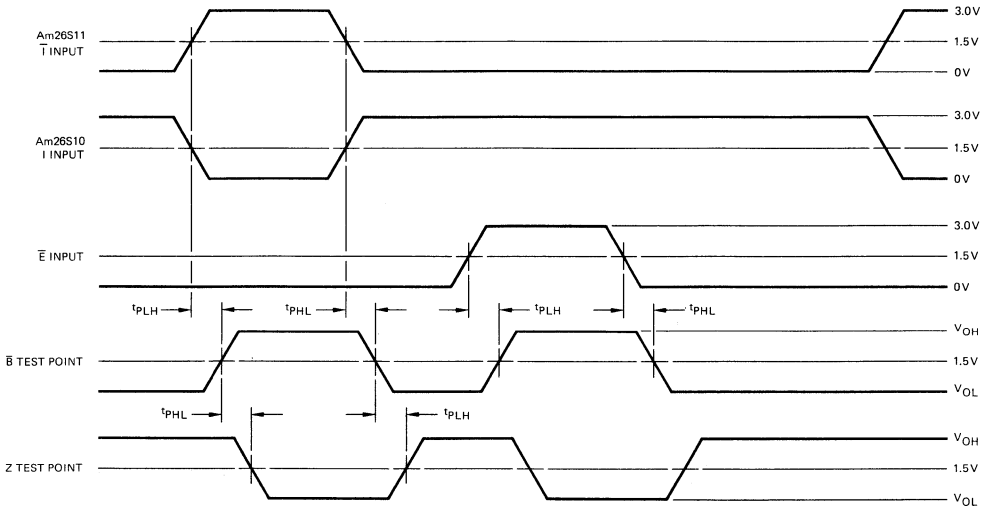
SWITCHING CHARACTERISTICS

TEST CIRCUIT



Note 1. Includes Probe and Jig Capacitance.

WAVEFORMS



Am26S12•Am26S12A

Quad Bus Transceiver

Distinctive Characteristics

- Quad high-speed bus transceivers
- Driver outputs can sink 100mA at 0.7V typically
- 100% reliability assurance testing in compliance with MIL-STD-883
- Choice of receiver hysteresis characteristics

FUNCTIONAL DESCRIPTION

The Am26S12 • Am26S12A are high-speed quad Bus Transceivers consisting of four high-speed bus drivers with open-collector outputs capable of sinking 100mA at 0.7 volts and four high-speed bus receivers. Each driver output is brought out and also connected internally to the high-speed bus receiver. The receiver has an input hysteresis characteristic and a TTL output capable of driving ten TTL Loads.

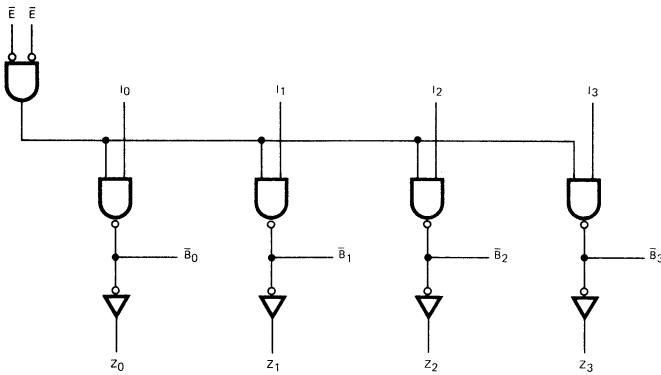
An active LOW, two-input AND gate controls the four drivers so that outputs of different device drivers can be connected together for party-line operation. The enable inputs can be conveniently driven by active LOW decoders such as the Am54S/74S139.

The high-drive capability in the LOW state allows party-line operation with a line impedance as low as 100Ω. The line can be terminated at both ends, and still give considerable noise margin at the receiver. The

hysteresis characteristic of the Am26S12 receiver is chosen so that the receiver output switches to a HIGH logic level when the receiver input is at a HIGH logic level and moves to 1.4 volts typically, and switches to a LOW logic level when the receiver input is at a LOW logic level and moves to 2.0 volts typically. This hysteresis characteristic makes the receiver very insensitive to noise on the bus.

The Am26S12A is functionally identical to the Am26S12 but has a different hysteresis characteristic so that the output switches with the input being typically at 1.2 volts or 2.25 volts. In both devices the threshold margin, the difference between the switching points, is greater than 0.4 volts.

LOGIC DIAGRAM/SYMBOL

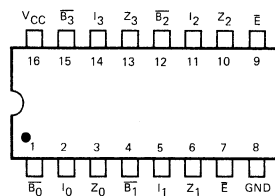


V_{CC} = PIN 16
GND = Pin 8

ORDERING INFORMATION

Package Type	Temperature Range	Am26S12 Order Number	Am26S12A Order Number
Molded DIP	0°C to +75°C	AM26S12PC	AM26S12APC
Hermetic DIP	0°C to +75°C	AM26S12DC	AM26S12ADC
Dice	0°C to +75°C	AM26S12XC	AM26S12AXC
Hermetic DIP	-55°C to +125°C	AM26S12DM	AM26S12ADM
Flat Pak	-55°C to +125°C	AM26S12FM	AM26S12AFM
Dice	-55°C to +125°C	AM26S12XM	AM26S12AXM

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

Am26S12/12A

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for High Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
Output Current, Into Outputs (BUS)	200mA
Output Current, Into Outputs (Receiver)	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am26S12XC-Am26S12AXC T_A = 0°C to +75°C V_{CC} = 5.0V ±5% (COM Range)
 Am26S12XM-Am26S12AXM T_A = -55°C to +125°C V_{CC} = 5.0V ±10% (MIL Range) Note 1

Parameters	Description	Test Conditions	Min.	Typ. (Note 2)	Max.	Units
I _{CC}	Power Supply Current	V _{CC} = MAX.		46	70	mA
I _{BUS}	Bus Leakage Current	V _{CC} = MAX. or 0V; V _{BUS} = 4.0V; Driver in OFF State			100	μA

Driver Characteristics

V _{OL} (Note 1)	Output LOW Voltage	V _{CC} = MIN. V _{IN} = V _{IH} or V _{IL}	COM'L	I _{OL} = 100mA	0.7	0.8	Volts
			MIL	I _{OL} = 60mA	0.55	0.7	Volts
				I _{OL} = 100mA	0.7	0.85	Volts
V _{IH}	Input HIGH Voltage				2.0		Volts
V _{IL}	Input LOW Voltage					0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA				-1.2	Volts
I _I	Input Current at Maximum Input Voltage	V _{CC} = MAX., V _I = 5.5V				1.0	mA
I _{IH}	Unit Load Input HIGH Current	V _{CC} = MAX., V _I = 2.4V			1.0	40	μA
I _{IL}	Unit Load Input LOW Current	V _{CC} = MAX., V _I = 0.4V			-0.4	-1.6	mA

Receiver Characteristics

V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -800μA V _{IN} = V _{IL} (Receiver)		2.4			Volts
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IL} (Receiver)			0.4	0.5	Volts
V _{IH}	Input HIGH Level Threshold	E = H	Am26S12	1.8	2.0	2.2	Volts
			Am26S12A	2.05	2.25	2.45	
V _{IL}	Input LOW Level Threshold	E = H	Am26S12	1.2	1.4	1.6	Volts
			Am26S12A	1.0	1.2	1.4	
V _{TM}	Input Threshold Margin	E = H		0.4			Volts
I _{OS}	Output Short Circuit Current	V _{CC} = MAX., V _{OUT} = 0.0V		-20		-55	mA

Notes: 1. For the Am26S12FM, Am26S12AFM the output current must be limited at 60mA or the maximum case temperature limited to 125°C for correct operation.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.

Switching Characteristics (T_A = 25°C, V_{CC} = 5.0V)

Parameters	Description	Conditions	Min.	Typ.	Max.	Units
t _{PLH}	Turn Off Delay Input to Bus	C _{LB} = 15pF, R _{LB} = 100Ω		7	11	ns
t _{PHL}	Turn On Delay Input to Bus	C _{LB} = 300pF, R _{LB} = 50Ω		14	21	ns
t _{PLH}	Turn Off Delay Enable to Bus	C _{LB} = 15pF, R _{LB} = 50Ω		10	15	ns
t _{PHL}	Turn On Delay Enable to Bus	C _{LB} = 15pF, R _{LB} = 50Ω		10	15	ns
t _{PLH}	Turn Off Delay Bus to Output	C _L = 15pF		18	26	ns
t _{PHL}	Turn On Delay Bus to Output	C _L = 15pF		18	26	ns

SWITCHING CIRCUITS AND WAVEFORMS

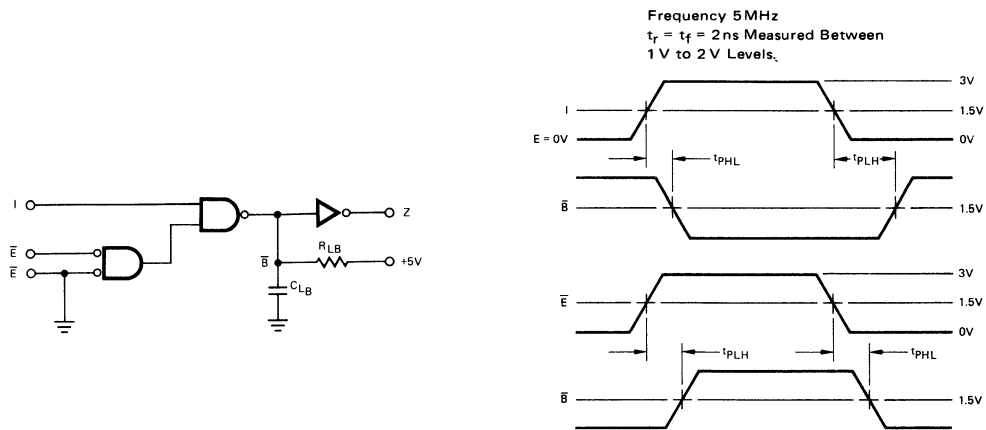


Figure 1. Bus Propagation Delays

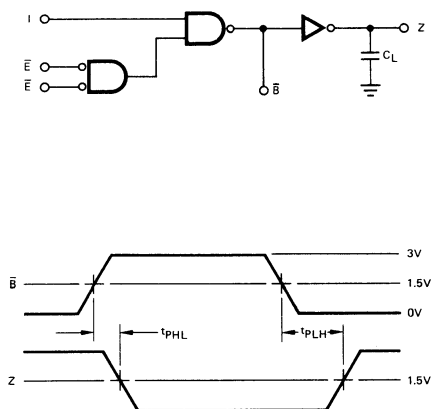


Figure 2. Receiver Propagation Delays

4

**TRUTH TABLE
Am26S12/26S12A**

Inputs		Outputs	
\bar{E}	I	\bar{B}	Z
L	L	H	L
L	H	L	H
H	X	Y	\bar{Y}

H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Don't Care
 Y = Voltage Level of Bus

Table I

MSI INTERFACING RULES

Interfacing Digital Family	Equivalent Input Unit Load	
	HIGH	LOW
Advanced Micro Devices 9300/2500 Series	1	1
FSC Series 9300	1	1
TI Series 54/7400	1	1
Signetics Series 8200	2	2
National Series DM 75/85	1	1
DTL Series 930	12	1

Table II

PERFORMANCE CURVES

Am26S12 Typical Receiver Input Characteristic

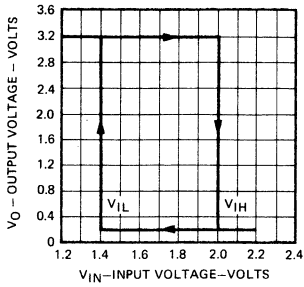


Figure 3

Am26S12A Typical Receiver Input Characteristic

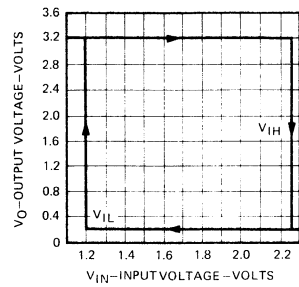


Figure 4

INPUT/OUTPUT CIRCUITRY

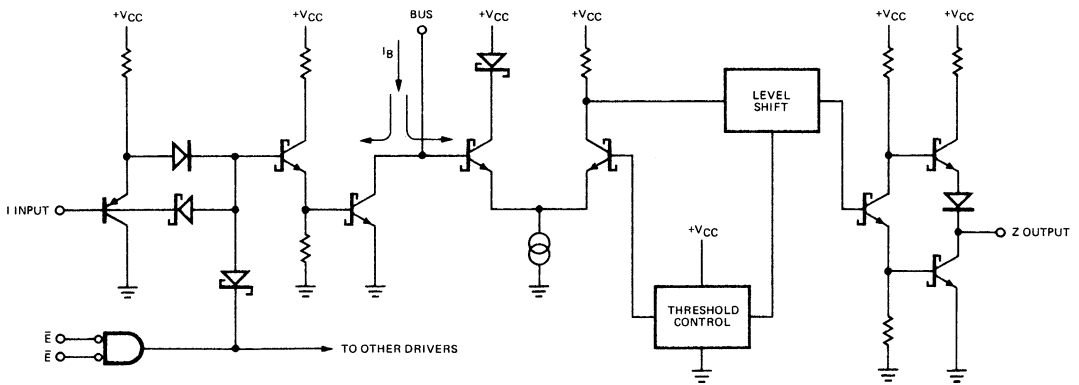


Figure 5

Am26S12/26S12A APPLICATION

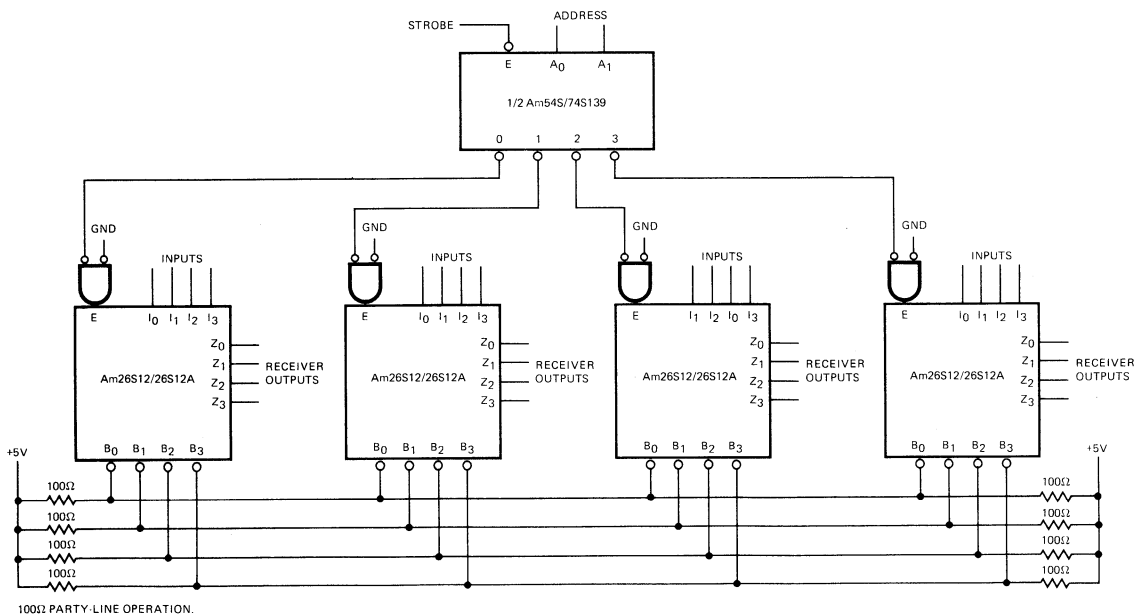
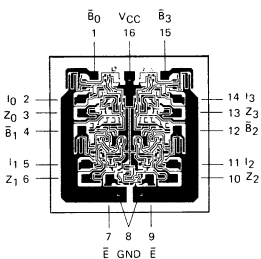


Figure 6

Metallization and Pad Layout



DIE SIZE: 0.071" x 0.072"

4

Am54S/74S138

3-Line to 8-Line Decoder/Demultiplexer

Distinctive Characteristics

- Advanced Schottky technology
- Inverting and non-inverting enable inputs

- Useful in memory decoders and high-speed data transmission
- 100% reliability assurance testing in compliance with MIL-STD-883

FUNCTIONAL DESCRIPTION

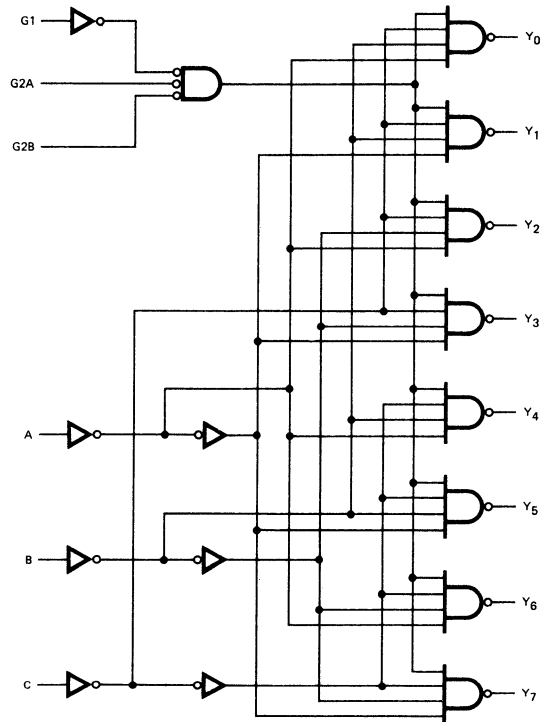
The Am54S/74S138 is a 3-line to 8-line decoder/demultiplexer fabricated using advanced Schottky technology. The decoder has three buffered select inputs A, B and C that are decoded to one of eight Y outputs.

One active-HIGH and two active-LOW enables can be used for gating the decoder or can be used with incoming data for demultiplexing applications. When the enable input function is in the disable state, all eight Y outputs are HIGH regardless of the A, B and C select inputs.

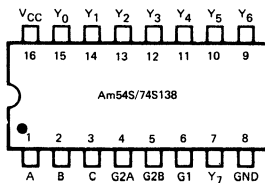
ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	SN74S138N
Hermetic DIP	0°C to +70°C	SN74S138J
Dice	0°C to +70°C	SN74S138X
Hermetic DIP	-55°C to +125°C	SN54S138J
Hermetic Flat Pak	-55°C to +125°C	SN54S138W
Dice	-55°C to +125°C	SN54S138X

LOGIC DIAGRAM

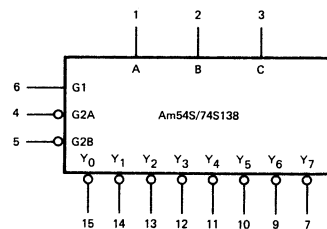


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am74S138	T _A = 0°C to +70°C	V _{CC} = 5.0V ±5% (COM'L)	MIN. = 4.75V	MAX. = 5.25V
Am54S138	T _A = -55°C to +125°C	V _{CC} = 5.0V ±10% (MIL)	MIN. = 4.5V	MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1mA V _{IN} = V _{IH} or V _{IL}	MIL 2.5 COM'L 2.7	3.4 3.4		Volts
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{IL} (Note 3)	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V			-2	mA
I _{IH} (Note 3)	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			50	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 0.0V	-40		-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)		49	74	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at V_{CC} = 5.0 V, 25°C ambient and maximum loading.
3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
5. Outputs enabled and open.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	Two Level Delay Select to Output	V _{CC} = 5V, C _L = 15pF, R _L = 280Ω		4.5	7	ns
t _{PHL}				7	10.5	
t _{PLH}	Three Level Delay Select to Output			7.5	12	ns
t _{PHL}				8	12	
t _{PLH}	G2A or G2B to Output			5	8	ns
t _{PHL}				7	11	
t _{PLH}	G1 to Output		7	11	ns	
t _{PHL}			7	11		

FUNCTION TABLE

Inputs				Outputs							
Enable			Select								
G1	G2A	G2B	C B A	Y ₀	Y ₁	Y ₂	Y ₃	Y ₄	Y ₅	Y ₆	Y ₇
L	X	X	X X X	H	H	H	H	H	H	H	H
X	H	X	X X X	H	H	H	H	H	H	H	H
X	X	H	X X X	H	H	H	H	H	H	H	H
H	L	L	L L L	L	H	H	H	H	H	H	H
H	L	L	L L H	H	L	H	H	H	H	H	H
H	L	L	L H L	H	H	L	H	H	H	H	H
H	L	L	L H H	H	H	H	L	H	H	H	H
H	L	L	H L L	H	H	H	H	L	H	H	H
H	L	L	H L H	H	H	H	H	H	L	H	H
H	L	L	H H L	H	H	H	H	H	H	L	H
H	L	L	H H H	H	H	H	H	H	H	L	L

H = HIGH
 L = LOW
 X = Don't care

LOADING RULES (In Unit Loads)

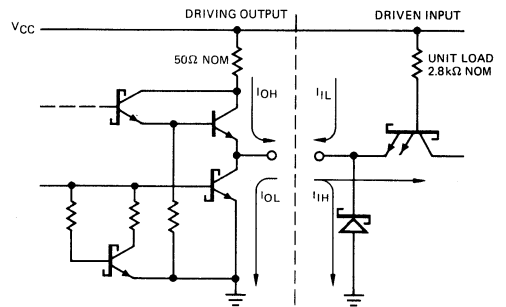
Input/Output	Pin No.'s	Unit Load	Fan-out	
			Output HIGH	Output LOW
A	1	1	—	—
B	2	1	—	—
C	3	1	—	—
G2A	4	1	—	—
G2B	5	1	—	—
G1	6	1	—	—
Y ₇	7	—	20	10
GND	8	—	—	—
Y ₆	9	—	20	10
Y ₅	10	—	20	10
Y ₄	11	—	20	10
Y ₃	12	—	20	10
Y ₂	13	—	20	10
Y ₁	14	—	20	10
Y ₀	15	—	20	10
V _{CC}	16	—	—	—

A Schottky TTL Unit Load is defined as 50µA measured at 2.7V HIGH and -2.0mA measured at 0.5V LOW.

DEFINITION OF FUNCTIONAL TERMS:

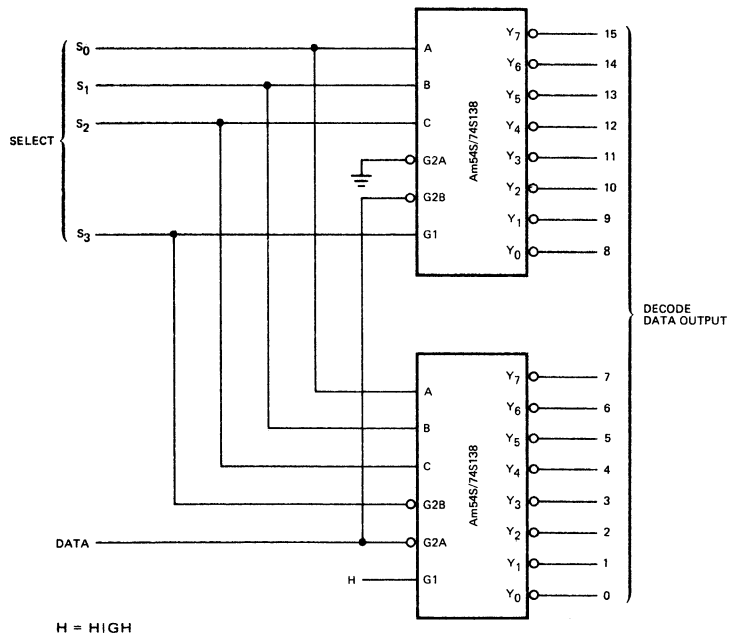
- A, B, C** Select. The three select inputs to the decoder.
- G1** The active-HIGH enable input. A LOW on the G1 input forces all Y outputs HIGH regardless of any other inputs.
- G2A, G2B** The active-LOW enable input. A HIGH on either the G2A or G2B input forces all Y outputs HIGH regardless of any other inputs.
- Y₀, Y₁, Y₂, Y₃, Y₄, Y₅, Y₆, Y₇** The eight decoder outputs.

SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



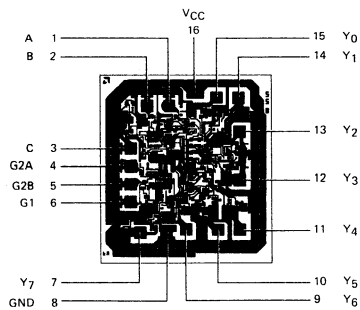
Note: Actual current flow direction shown.

APPLICATION



ONE-OF-SIXTEEN DEMULTIPLEXER

Metallization and Pad Layout



DIE SIZE 0.065" X 0.070"

Am54S/74S139 • Am93S21

Dual 2-Line to 4-Line Decoder/Demultiplexer

Distinctive Characteristics

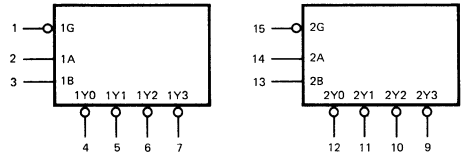
- Advanced Schottky technology
- 7.5ns typical propagation delay
- Two independent decoders/demultiplexers
- 100% reliability assurance testing in compliance with MIL-STD-883.

FUNCTIONAL DESCRIPTION

The Am54S/74S139 and Am93S21 are dual 2-line to 4-line decoder/demultiplexer units fabricated using advanced Schottky technology. Each decoder has two buffered select inputs A and B which are decoded to one of four Y outputs.

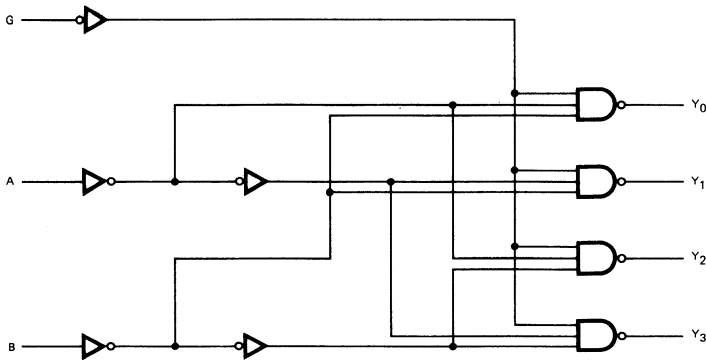
An active LOW enable can be used for gating or can be used as a data input for demultiplexing applications. When the enable is HIGH, all four Y outputs are HIGH, regardless of the A and B inputs.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

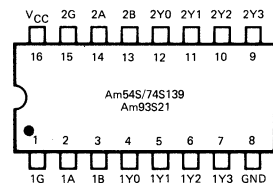
LOGIC DIAGRAM (One Decoder Shown)



ORDERING INFORMATION

Package Type	Temperature Range	Am54S/ 74S139	Am93S21
		Order Number	Order Number
Molded DIP	0° C to +70° C	SN74S139N	93S21PC
Hermetic DIP	0° C to +70° C	SN74S139J	93S21DC
Dice	0° C to +70° C	SN74S139X	93S21XC
Hermetic DIP	-55° C to +125° C	SN54S139J	93S21DM
Hermetic Flat Pak	-55° C to +125° C	SN54S139W	93S21FM
Dice	-55° C to +125° C	SN54S139X	93S21XM

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 V to +7 V
DC Voltage Applied to Outputs for HIGH Output State	-5.0V to +V _{CC} max.
DC Input Voltage	-0.5 V to +5.5 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am74S139, Am93S21XC	T _A = 0°C to +70°C	V _{CC} = 5.0V ± 5% (COM'L)	MIN. = 4.75V	MAX. = 5.25V
Am54S139, Am93S21XM	T _A = -55°C to +125°C	V _{CC} = 5.0V ± 10% (MIL)	MIN. = 4.5V	MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)		Max.	Units
				MIL	COM'L		
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1mA V _{IN} = V _{IH} or V _{IL}	2.5	3.4			Volts
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5		Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2				Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8		Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2		Volts
I _{IL} (Note 3)	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5 V			-2		mA
I _{IH} (Note 3)	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7 V			50		μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5 V			1.0		mA
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 0.0 V	-40		-100		mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)		60	90		mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Actual input currents = Unit Load Current X Input Load Factor (See Loading Rules).
 4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 5. I_{CC} is measured with all outputs enabled and open.

4

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	Select to Output, 2 Levels of Delay	V _{CC} = 5.0V, R _L = 280Ω, C _L = 15pF		5	7.5	ns
t _{PHL}				6.5	10	
t _{PLH}	Select to Output, 3 Levels of Delay			7	12	ns
t _{PHL}				8	12	
t _{PLH}	Enable to Output, 2 Levels of Delay			5	8	ns
t _{PHL}				6.5	10	

FUNCTION TABLE

INPUTS			OUTPUTS			
ENABLE G	SELECT		Y ₀	Y ₁	Y ₂	Y ₃
	B	A				
H	X	X	H	H	H	H
L	L	L	L	H	H	H
L	L	H	H	L	H	H
L	H	L	H	H	L	H
L	H	H	H	H	H	L

H = HIGH
L = LOW
X = Don't Care

DEFINITION OF FUNCTIONAL TERMS

A, B Select. The two select inputs to the decoder.

G Enable. The enable input to the decoder. A HIGH input forces all four Y outputs HIGH regardless of the A and B inputs.

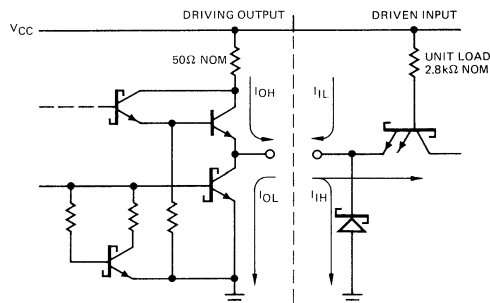
Y₀, Y₁, Y₂, Y₃ The four decoder outputs.

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Unit Load	Fan-out	
			Output HIGH	Output LOW
1G	1	1	—	—
1A	2	1	—	—
1B	3	1	—	—
1Y ₀	4	—	20	10
1Y ₁	5	—	20	10
1Y ₂	6	—	20	10
1Y ₃	7	—	20	10
GND	8	—	—	—
2Y ₃	9	—	20	10
2Y ₂	10	—	20	10
2Y ₁	11	—	20	10
2Y ₀	12	—	20	10
2B	13	1	—	—
2A	14	1	—	—
2G	15	1	—	—
V _{CC}	16	—	—	—

A Schottky TTL Unit Load is defined as 50µA measured at 2.7V HIGH and -2.0mA measured at 0.5V LOW.

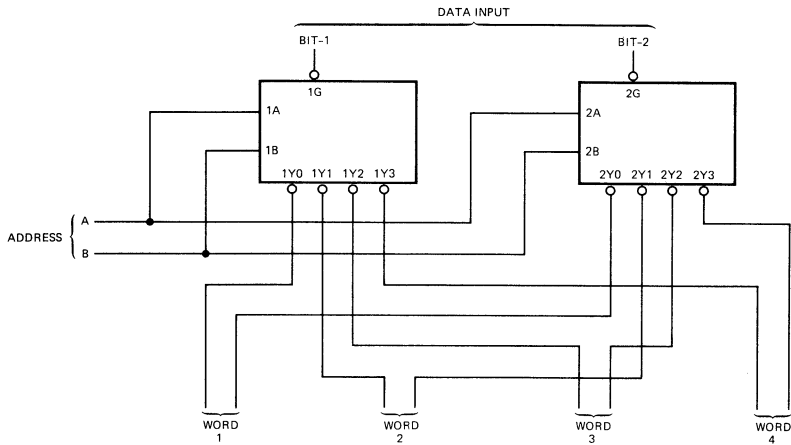
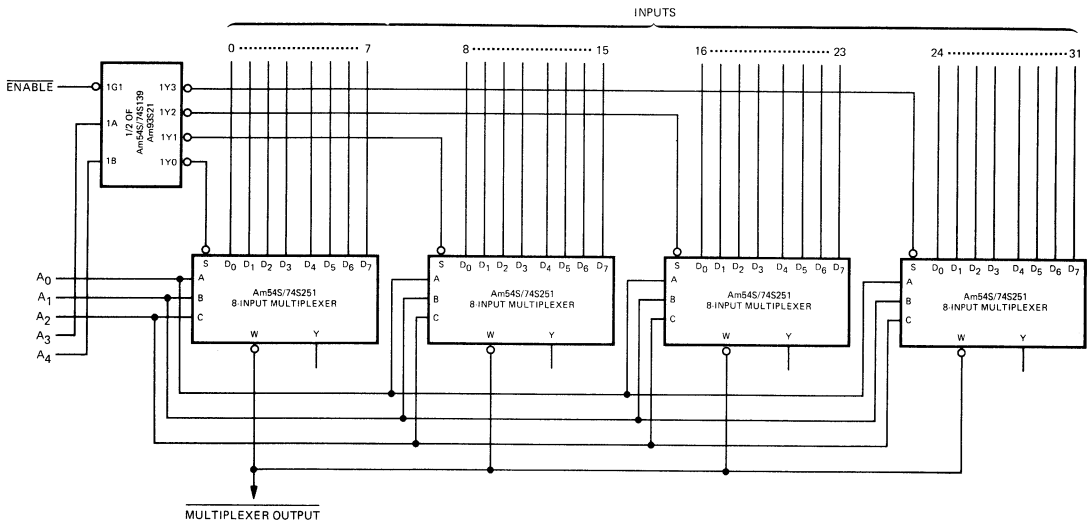
SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

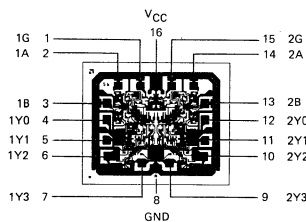
APPLICATIONS

32-Input Multiplexer



Data routing using one Am54S/74S139 as a demultiplexer for two bits.

Metallization and Pad Layout



DIE SIZE 0.073" X 0.060"

Am54S/74S151·Am54S/74S251

Eight-Input Multiplexers

Distinctive Characteristics

- Advanced Schottky technology
- Switches one of eight inputs to two complementary outputs

- Three-state output on Am54S/74S251 for bus organized systems
- 100% reliability assurance testing in compliance with MIL-STD-883

FUNCTIONAL DESCRIPTION

The Am54S/74S151 and the Am54S/74S251 are eight-input multiplexers that switch one of eight inputs onto the inverting and non-inverting outputs under the control of a three-bit select code. The inverting output is one gate delay faster than the non-inverting output.

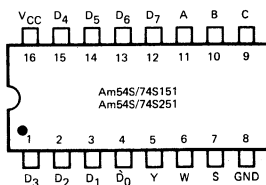
The Am54S/74S151 provides an active-LOW strobe. When the strobe is HIGH, the inverting output (W) is HIGH and the non-inverting output (Y) is LOW.

The Am54S/74S251 features a three-state output for data bus organization. The active-LOW strobe, or "output control" applies to both the inverting and non-inverting output. When the output control is HIGH, the outputs are in the high-impedance state. When the output control is LOW, the active pull-up output is enabled.

ORDERING INFORMATION

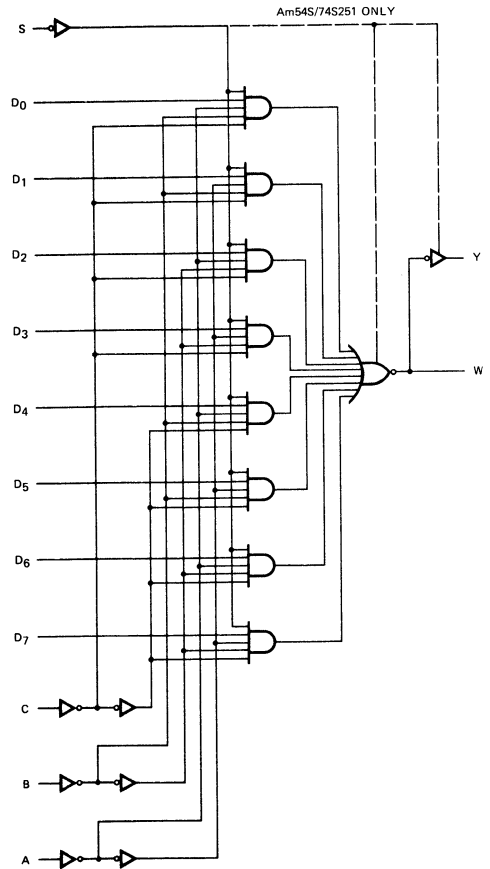
Package Type	Temperature Range	Am54S/74S151 Order Number	Am54S/74S251 Order Number
Molded DIP	0°C to +70°C	SN74S151N	SN74S251N
Hermetic DIP	0°C to +70°C	SN74S151J	SN74S251J
Dice	0°C to +70°C	SN74S151X	SN74S251X
Hermetic DIP	-55°C to +125°C	SN54S151J	SN54S251J
Hermetic Flat Pak	-55°C to +125°C	SN54S151W	SN54S251W
Dice	-55°C to +125°C	SN54S151X	SN54S251X

CONNECTION DIAGRAM Top View

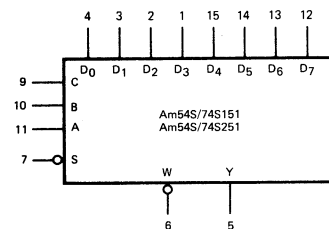


Note: Pin 1 is marked for orientation.

LOGIC DIAGRAM



LOGIC SYMBOL



VCC = Pin 16
GND = Pin 8

MAXIMUM RATINGS (Above which the useful life may be impaired).

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Output	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am74S151, Am74S251	T _A = 0°C to +70°C	V _{CC} = 5.0V ±5% (COM'L)	MIN. = 4.75V	MAX. = 5.25V
Am54S151, Am54S251	T _A = -55°C to +125°C	V _{CC} = 5.0V ±10% (MIL)	MIN. = 4.5V	MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., V _{IN} = V _{IH} or V _{IL}	I _{OH} = -1mA	2.5	3.4	Volts
			I _{OH} = -2mA	2.7	3.4	
			I _{OH} = -6.5mA	2.4	3.4	
				2.4	3.2	
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{IL} (Note 3)	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5			-2	mA
	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			50	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1	mA
I _{O(off)}	Off-State (High-Impedance) Output Current (S251 only)	V _{CC} = MAX. V _{IN} = V _{IH} or V _{IL}	V _O = 2.4V		50	μA
			V _O = 0.5V		-50	
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 0.0V	-40		-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)	S151	45	70	mA
			S251	55	85	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
5. I_{CC} is measured with all outputs open and all inputs at 4.5V.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units	
t _{PLH}	A, B, or C to Y; 4 Levels of Delay (S151 only)	V _{CC} = 5.0V, R _L = 280Ω, C _L = 15 pF		12	18	ns	
t _{PHL}				12	18		
t _{PLH}	A, B, or C to Y; 4 Levels of Delay (S251 only)			12	18	ns	
t _{PHL}				13	19.5		
t _{PLH}	A, B, or C to W; 3 Levels of Delay			10	15	ns	
t _{PHL}				9	13.5		
t _{PLH}	Any D to Y			8	12	ns	
t _{PHL}				8	12		
t _{PLH}	Any D to W			4.5	7	ns	
t _{PHL}				4.5	7		
t _{PLH}	Strobe to Y (S151 only)			11	16.5	ns	
t _{PHL}				12	18		
t _{PLH}	Strobe to W (S151 only)		9	13	ns		
t _{PHL}			8.5	12			
t _{ZH}	Output Enable to Y (S251 only)	V _{CC} = 5.0V, R _L = 280Ω, C _L = 15 pF		13	19.5	ns	
t _{ZL}				14	21		
t _{ZH}	Output Enable to W (S251 only)			13	19.5	ns	
t _{ZL}				14	21		
t _{HZ}	Output Enable to Y (S251 only)		V _{CC} = 5.0V, R _L = 280Ω, C _L = 5 pF		5.5	8.5	ns
t _{LZ}					9	14	
t _{HZ}	Output Enable to W (S251 only)			5.5	8.5	ns	
t _{LZ}				9	14		

FUNCTION TABLE

INPUTS					OUTPUTS			
SELECT			S151 Strobe	S251 Output Control	S151 Output		S251 Output	
C	B	A	S	S	Y	W	Y	W
X	X	X	H	H	L	H	Z	Z
L	L	L	L	L	D ₀	\bar{D}_0	D ₀	\bar{D}_0
L	L	H	L	L	D ₁	\bar{D}_1	D ₁	\bar{D}_1
L	H	L	L	L	D ₂	\bar{D}_2	D ₂	\bar{D}_2
L	H	H	L	L	D ₃	\bar{D}_3	D ₃	\bar{D}_3
H	L	L	L	L	D ₄	\bar{D}_4	D ₄	\bar{D}_4
H	L	H	L	L	D ₅	\bar{D}_5	D ₅	\bar{D}_5
H	H	L	L	L	D ₆	\bar{D}_6	D ₆	\bar{D}_6
H	H	H	L	L	D ₇	\bar{D}_7	D ₇	\bar{D}_7

H = HIGH

X = Don't Care

L = LOW

Z = High Impedance

D₀-D₇ = The output will follow the HIGH-level or LOW-level of the selected input.

\bar{D}_0 - \bar{D}_7 = The output will follow the complement of the HIGH-level or LOW-level of the selected input.

DEFINITION OF FUNCTIONAL TERMS

A, B, C The three select inputs of the multiplexer.

D₀, D₁, D₂, D₃.

D₄, D₅, D₆, D₇ The eight data inputs of the multiplexer.

Y The true multiplexer output.

W The complement multiplexer output.

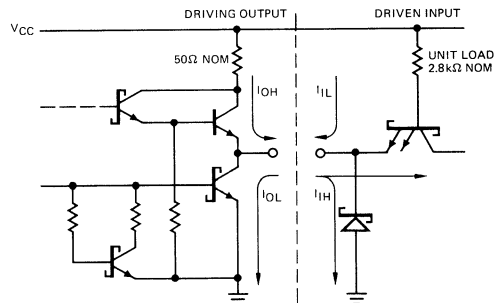
S Strobe. On the Am54S/74S151, a HIGH on the strobe forces the Y output LOW and the W output HIGH.

S Output Control. On the Am54S/74S251, a HIGH on the output control (or strobe) forces both the W and Y outputs to the high-impedance (off) state.

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
D ₃	1	1	-	-
D ₂	2	1	-	-
D ₁	3	1	-	-
D ₀	4	1	-	-
Y	5	-	20	10
W	6	-	20	10
S	7	1	-	-
GND	8	-	-	-
C	9	1	-	-
B	10	1	-	-
A	11	1	-	-
D ₇	12	1	-	-
D ₆	13	1	-	-
D ₅	14	1	-	-
D ₄	15	1	-	-
V _{CC}	16	-	-	-

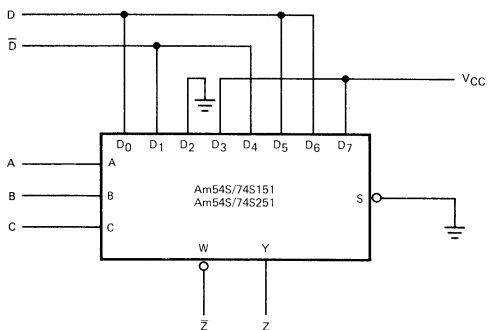
A Schottky TTL Unit Load is defined as 50 μ A measured at 2.7V HIGH and -2.0mA measured at 0.5V LOW.

SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS

Note: Actual current flow direction shown.

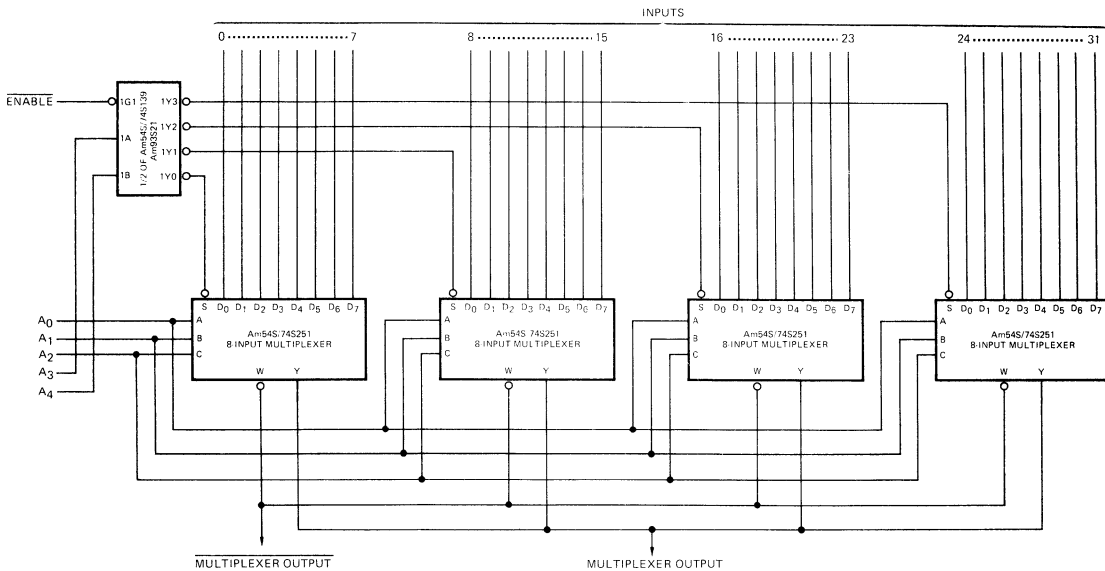
APPLICATIONS

LOGIC FUNCTION GENERATION



$$Z = \bar{A}\bar{B}CD + \bar{A}BC\bar{D} + A\bar{C}D + AB + AC\bar{D} + BC\bar{D}$$

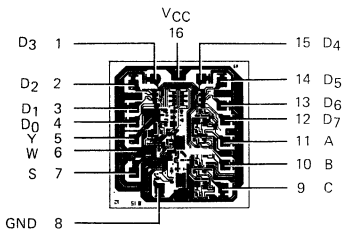
32-INPUT MULTIPLEXER



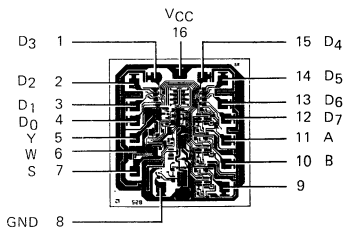
4

Metalization and Pad Layout

Am54S/74S151



Am54S/74S251



DIE SIZE: 0.064" X 0.067"

Am54S/74S153 • Am54S/74S253

Dual 4-Line To 1-Line Data Selectors/Multiplexers

Distinctive Characteristics

- Permits multiplexing from N lines to 1 line.
- Performs parallel-to-serial conversion.

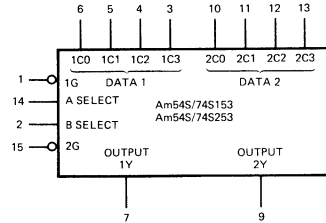
- Am54S/74S253 provides three-state outputs for data bus organization.
- 100% reliability assurance testing in compliance with MIL-STD-883.

FUNCTIONAL DESCRIPTION

These dual four-input multiplexers provide the digital equivalent of a two-pole, four position switch with the position of both switches set by the logic levels supplied to the select inputs A and B. Each section of the Am54S/74S153 has a separate active-LOW enable (strobe) input that forces the output of that section LOW when a HIGH level is applied regardless of the other inputs.

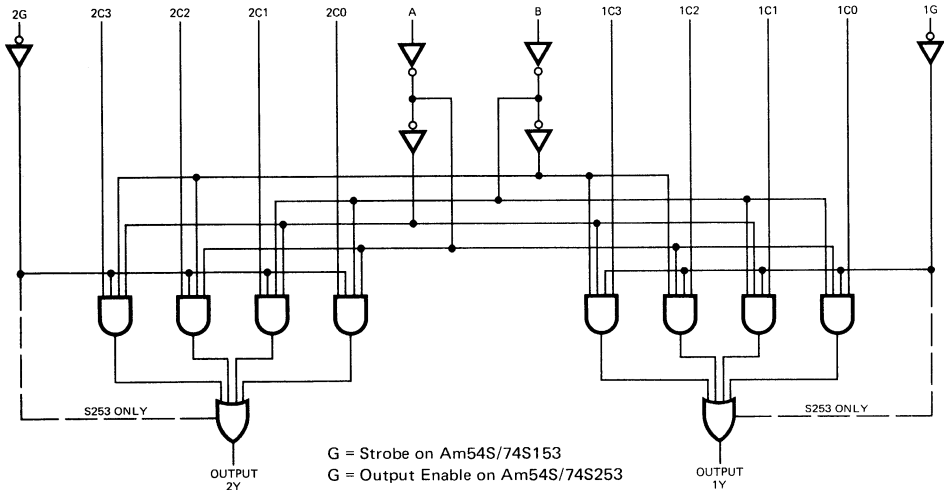
The Am54S/74S253 features a three-state output to interface with bus-organized systems. Each section of the Am54S/74S253 has a separate active-LOW output control that disables the output driver (high-impedance state) of that section when a HIGH logic level is applied regardless of the other inputs.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

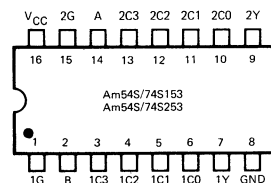
LOGIC DIAGRAM



ORDERING INFORMATION

Package Type	Temperature Range	Am54S/74S153 Order Number	Am54S/74S253 Order Number
Molded DIP	0°C to +70°C	SN74S153N	SN74S253N
Hermetic DIP	0°C to +70°C	SN74S153J	SN74S253J
Dice	0°C to +70°C	SN74S153X	SN74S253X
Hermetic DIP	-55°C to +125°C	SN54S153J	SN54S253J
Hermetic Flat Pak	-55°C to +125°C	SN54S153W	SN54S253W
Dice	-55°C to +125°C	SN54S153X	SN54S253X

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 V to +7 V
DC Voltage Applied to Outputs for HIGH Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +5.5 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am74S153, Am74S253	T _A = 0°C to +70°C	V _{CC} = 5.0 V ± 5% (COM'L)	MIN. = 4.75 V	MAX. = 5.25 V
Am54S153, Am54S253	T _A = -55°C to +125°C	V _{CC} = 5.0 V ± 10% (MIL)	MIN. = 4.5 V	MAX. = 5.5 V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., V _{IN} = V _{IH} or V _{IL}	I _{OH} = -1 mA	2.5	3.4	Volts	
			I _{OH} = -2 mA	2.4	3.4		
			I _{OH} = -6.5 mA	2.4	3.2		
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20 mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2			Volts	
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18 mA			-1.2	Volts	
I _{IL} (Note 3)	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5 V			-2	mA	
I _{IH} (Note 3)	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7 V			50	μA	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5 V			1	mA	
I _O	Off-State (HIGH Impedance) Output Current Am54S/74S253 Only	V _{CC} = MAX.	V _O = 2.4 V			50	μA
			V _O = 0.5 V			-50	
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 0.0 V	-40			-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)	S153		45	70	mA
			S253		55	85	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at V_{CC} = 5.0 V, 25°C ambient and maximum loading.
3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
5. I_{CC} is measured with all outputs open and all inputs grounded.

4

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units	
t _{PLH}	Data to Output	V _{CC} = 5.0 V, R _L = 280 Ω, C _L = 15 pF		6	9	ns	
t _{PHL}				6	9		
t _{PLH}	Select to Output			11.5	18	ns	
t _{PHL}				12	18		
t _{PLH}	Strobe to Output		S153		10	15	ns
t _{PHL}			S153		9	13.5	
t _{ZH}	Output Control to Output	S253		13	19.5	ns	
t _{ZL}		S253		14	21		
t _{HZ}	Output Control to Output	S253		5.5	8.5	ns	
t _{LZ}		S253		9	14		

FUNCTION TABLE

INPUTS							OUTPUTS			
Select		Data				S153 Strobe	S253 Output Control	S153 Output	S253 Output	
B	A	C ₀	C ₁	C ₂	C ₃	G	G	Y	Y	
X	X	X	X	X	X	H	H	L	Z	
L	L	L	X	X	X	L	L	L	L	
L	L	H	X	X	X	L	L	H	H	
L	H	X	L	X	X	L	L	L	L	
L	H	X	H	X	X	L	L	H	H	
H	L	X	X	L	X	L	L	L	L	
H	L	X	X	H	X	L	L	H	H	
H	H	X	X	X	L	L	L	L	L	
H	H	X	X	X	H	L	L	H	H	

H = HIGH

X = Don't Care

L = LOW

Z = High Impedance

Note: A & B are common to both 4 input multiplexers.

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out Output	
			HIGH	LOW
1G	1	1	—	—
B	2	1	—	—
1C3	3	1	—	—
1C2	4	1	—	—
1C1	5	1	—	—
1C0	6	1	—	—
1Y	7	—	20*	10
GND	8	—	—	—
2Y	9	—	20*	10*
2C0	10	1	—	—
2C1	11	1	—	—
2C2	12	1	—	—
2C3	13	1	—	—
A	14	1	—	—
2G	15	1	—	—
V _{CC}	16	—	—	—

A Schottky TTL Unit Load is defined at 50 μ A measured at 2.7V HIGH and -2.0 mA measured at 0.5V LOW.

* 20 for the Am54S/74S153

40 for the Am54S253

130 for the Am74S253

DEFINITION OF FUNCTIONAL TERMS:

1C_i, 2C_i Data Inputs. The four data inputs to each multiplexer; $i = 0, 1, 2,$ and 3 .

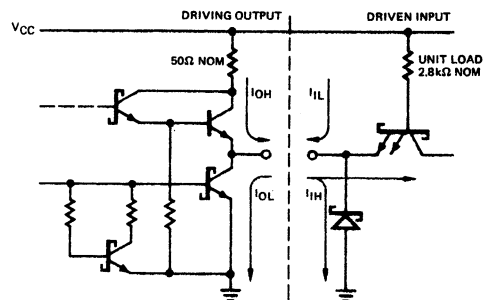
1Y, 2Y Multiplexer Outputs. The output of each four-input multiplexer.

A, B Select Inputs. The inputs used to determine which of the four data inputs are selected for the output.

G (Am54S/74S153) Strobe. An active-LOW strobe used to enable the output. A HIGH level input forces the output LOW regardless of the other inputs.

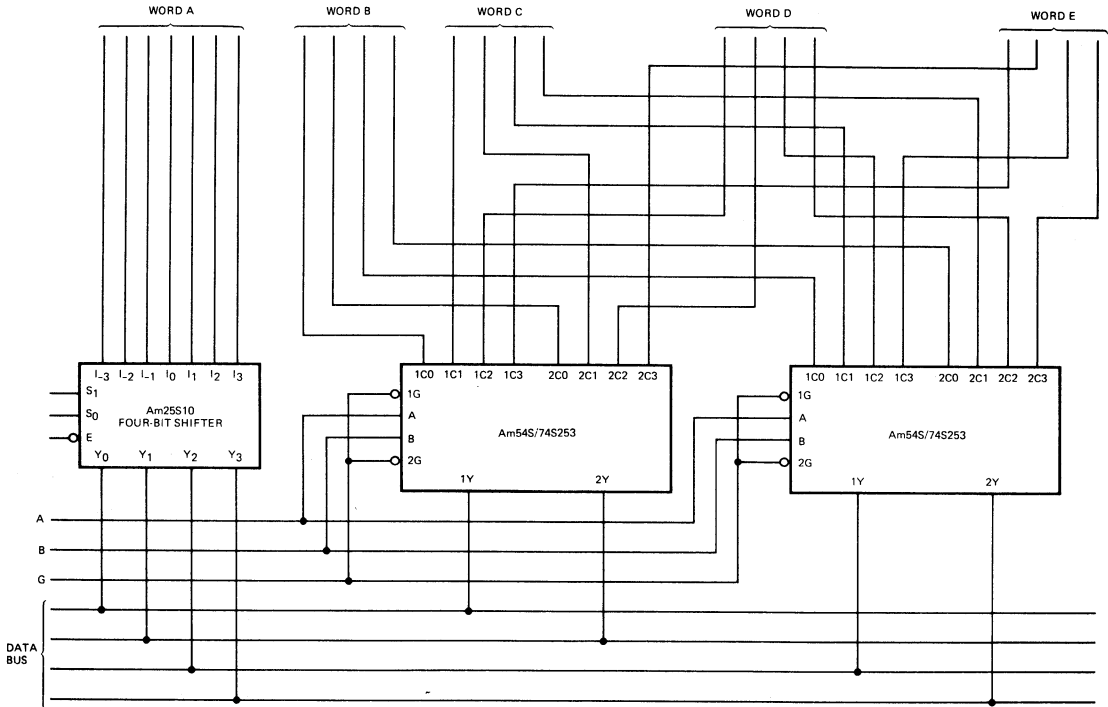
G (Am54S/74S253) Output Control. An active-LOW three-state control used to enable the output. A HIGH level input forces the output to the high-impedance (off) state.

SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown

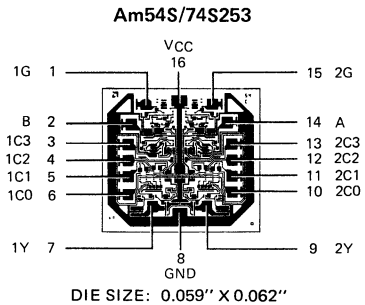
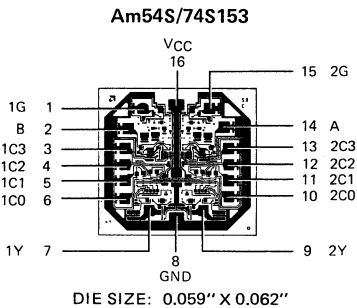
APPLICATIONS



Am54S/74S253 Dual 4-Input Multiplexer in a Bus-Organized System

4

Metallization and Pad Layout



Am54S/74S157 • Am54S/74S158 • Am93S22

Quadruple 2-Line To 1-Line Data Selectors/Multiplexers

Distinctive Characteristics

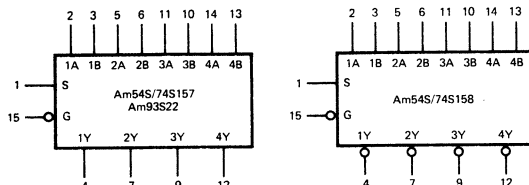
- Schottky clamp provides improved A-C performance.
- Selects four of eight data inputs with single select line and over-riding strobe.
- Inverting or non-inverting data output configurations.
- 100% reliability assurance testing in compliance with MIL-STD-883

FUNCTIONAL DESCRIPTION

These data selectors/multiplexers are used to select a 4-bit word from one of two sources. The four outputs at the Am54S/74S157 • Am93S22 present true data with respect to the input data. The four outputs of the Am54S/74S158 present inverted data with respect to the inputs and also minimize propagation delay. A common active-HIGH strobe (active-LOW enable) is provided on all devices.

A single select line, S, is used to select one of the two multiplexer input words. When the select is LOW, the A input word is present at the output. When the select is HIGH, the B input word is present at the output.

LOGIC SYMBOLS

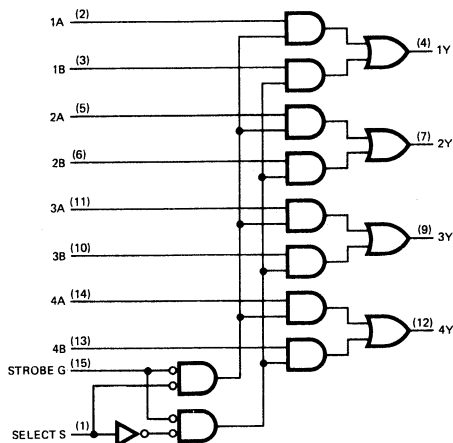


V_{CC} = Pin 16
GND = Pin 8

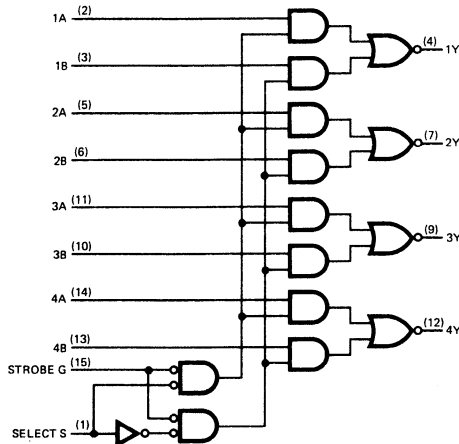
V_{CC} = Pin 16
GND = Pin 8

LOGIC DIAGRAMS

Am54S/74S157 • Am93S22



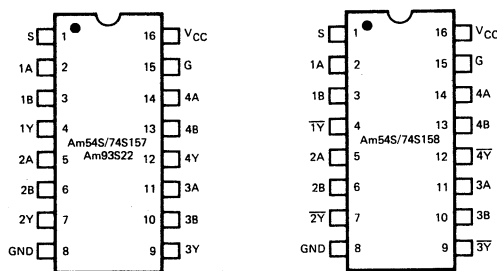
Am54S/74S158



ORDERING INFORMATION

Part Number	Package Type	Temperature Range	Order Number
Am54S/ 74S157	Molded DIP	0°C to +70°C	SN74S157N
	Hermetic DIP	0°C to +70°C	SN74S157J
	Dice	0°C to +70°C	SN74S157X
	Hermetic DIP	-55°C to +125°C	SN54S157J
	Hermetic Flat Pak	-55°C to +125°C	SN54S157W
	Dice	-55°C to +125°C	SN54S157X
Am54S/ 74S158	Molded DIP	0°C to +70°C	SN74S158N
	Hermetic DIP	0°C to +70°C	SN74S158J
	Dice	0°C to +70°C	SN74S158X
	Hermetic DIP	-55°C to +125°C	SN54S158J
	Hermetic Flat Pak	-55°C to +125°C	SN54S158W
	Dice	-55°C to +125°C	SN54S158X
Am93S22	Molded DIP	0°C to +70°C	93S22PC
	Hermetic DIP	0°C to +70°C	93S22DC
	Dice	0°C to +70°C	93S22XC
	Hermetic DIP	-55°C to +125°C	93S22DM
	Hermetic Flat Pak	-55°C to +125°C	93S22FM
	Dice	-55°C to +125°C	93S22XM

CONNECTIONS DIAGRAMS Top Views



Note: Pin 1 is marked for orientation.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am74S157, Am74S158, Am93S22XC	T _A = 0°C to +70°C	V _{CC} = 5.0V ± 5% (COM'L)	MIN. = 4.75V	MAX. = 5.25V
Am54S157, Am54S158, Am93S22XM	T _A = -55°C to +125°C	V _{CC} = 5.0V ± 10% (MIL)	MIN. = 4.5V	MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ.(Note 2)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1mA V _{IN} = V _{IH} or V _{IL}	MIL	2.5	3.4	Volts	
			COM'L	2.7	3.4		
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2			Volts	
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts	
I _{IL} (Note 3)	Input LOW Current	S or G A or B	V _{CC} = MAX., V _{IN} = 0.5V		-4	mA	
					-2		
I _{IH} (Note 3)	Input HIGH Current	S or G A or B	V _{CC} = MAX., V _{IN} = 2.7V		100	μA	
					50		
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1	mA	
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 0.0V	-40		-100	mA	
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)	S157		50	78	mA
			S158		39	61	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
5. I_{CC} is measured with all outputs open and 4.5V applied to all inputs.

4

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	Data to Output	V _{CC} = 5.0V, C _L = 15pF, R _L = 280Ω	S157	5	7.5	ns
			S158	4	6	
t _{PHL}	Data to Output		S157	4.5	6.5	ns
			S158	4	6	
t _{PLH}	Strobe to Output		S157	8.5	12.5	ns
			S158	6.5	11.5	
t _{PHL}	Strobe to Output		S157	7.5	12	ns
			S158	7	12	
t _{PLH}	Select to Output		S157	9.5	15	ns
			S158	8	12	
t _{PHL}	Select to Output	S157	9.5	15	ns	
		S158	8	12		

FUNCTION TABLE

INPUTS				OUTPUTS	
Strobe G	Select S	Data A	Data B	S157 Y	S158 Y
H	X	X	X	L	H
L	L	L	X	L	H
L	L	H	X	H	L
L	H	X	L	L	H
L	H	X	H	H	L

H = HIGH

L = LOW

X = Don't Care

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
S	1	2	—	—
1A	2	1	—	—
1B	3	1	—	—
1Y	4	—	20	10
2A	5	1	—	—
2B	6	1	—	—
2Y	7	—	20	10
GND	8	—	—	—
3Y	9	—	20	10
3B	10	1	—	—
3A	11	1	—	—
4Y	12	—	20	10
4B	13	1	—	—
4A	14	1	—	—
G	15	2	—	—
V _{CC}	16	—	—	—

A Schottky TTL Unit Load is defined as 50 μ A measured at 2.7V HIGH and -2.0mA measured at 0.5V LOW.

DEFINITION OF FUNCTIONAL TERMS

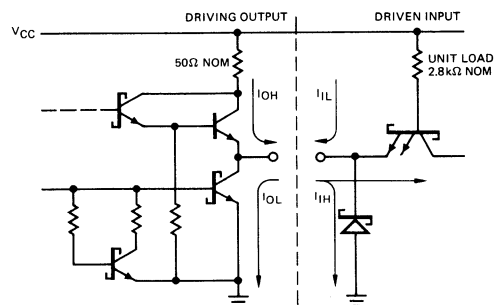
1A, 2A, 3A, 4A The data inputs for the 4-bits of the A word.

1B, 2B, 3B, 4B The data inputs for the 4-bits of the B word.

1Y, 2Y 3Y, 4Y The four outputs of the multiplexer.

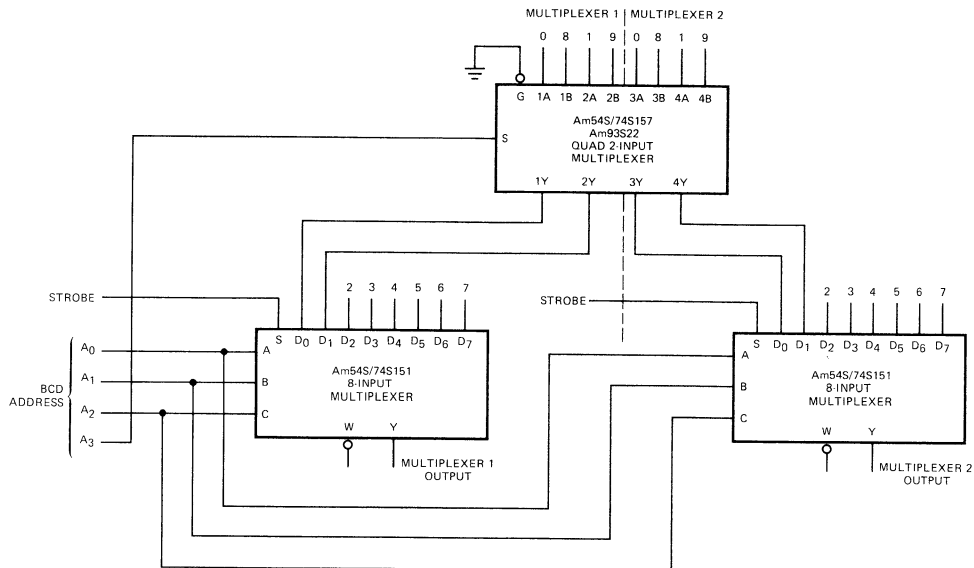
G Strobe When the strobe is HIGH, the four outputs of the Am54S/74S157 (Am93S22) are LOW and the outputs of the Am54S/74S158 are HIGH. When the strobe is LOW, the devices are enable to pass data.

S Select When the select input is LOW, the A word is present at the output. When the select input is HIGH, the B word is present at the output.

SCHOTTKY INPUT/OUTPUT
CURRENT INTERFACE CONDITIONS

Note: Actual current flow direction shown.

APPLICATION



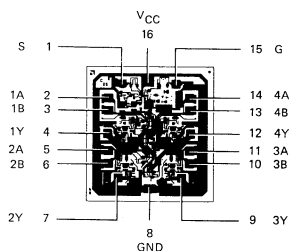
Dual 10-Input Multiplexer

Two 10-input multiplexers are shown above with the select lines common to the two multiplexers. Inputs are selected by an 8421 BCD Address.

4

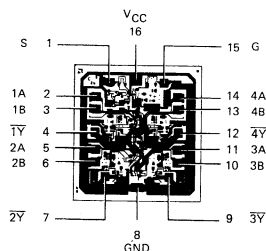
Metallization and Pad Layouts

Am54S/74S157



DIE SIZE 0.065" X 0.069"

Am54S/74S158



DIE SIZE 0.065" X 0.069"

Am54S/74S160 • Am54S/74S161

BCD Decade/Four-Bit Binary Counters

Distinctive Characteristics

- Fully synchronous counting
- Fully synchronous parallel loading
- Edge-triggered clock action

- Advanced Schottky technology
- 100% reliability assurance testing in compliance with MIL-STD-883

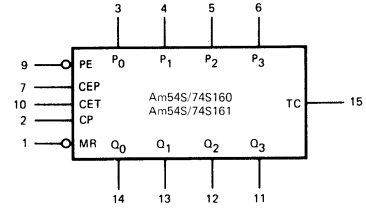
FUNCTIONAL DESCRIPTION

The Am54S/74S160 and Am54S/74S161 are fully synchronous 4-bit decimal and binary counters. With the parallel enable (\overline{PE}) LOW, data on the P_0 - P_3 inputs is parallel loaded on the positive clock transition. When \overline{PE} is HIGH and both count enables CEP and CET are also HIGH, counting will occur on the LOW-to-HIGH clock transition.

The terminal count state (1001 for the Am54S/74S160 and 1111 for the Am54S/74S161) is decoded with CET in the terminal count (TC) output. If CET is HIGH and the counter is in its terminal count state, then TC is HIGH.

Both counters have an asynchronous master reset (\overline{MR}). A LOW on the \overline{MR} input forces the Q outputs LOW independent of all other inputs. The only requirements on the \overline{PE} , CEP, CET and P_0 - P_3 inputs is that they meet the set-up time requirements before the clock LOW-to-HIGH transition.

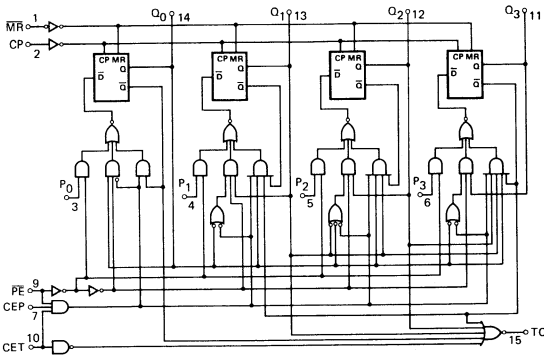
LOGIC SYMBOL



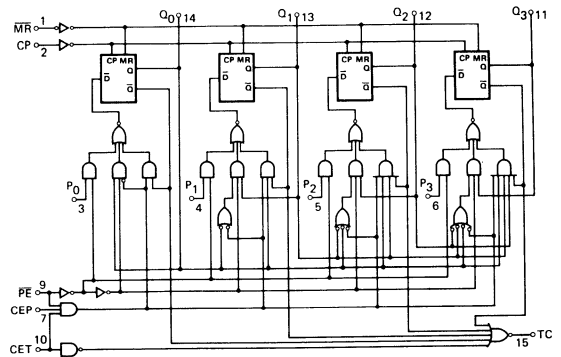
V_{CC} = Pin 16
GND = Pin 8

LOGIC DIAGRAMS

Am54S/74S160



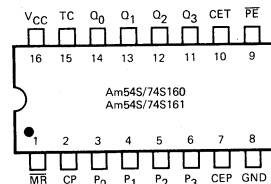
Am54S/74S161



ORDERING INFORMATION

Package Type	Temperature Range	Am54S/74S160 Order Number	Am54S/74S161 Order Number
Molded DIP	0° C to +75° C	SN74S160N	SN74S161N
Hermetic DIP	0° C to +75° C	SN74S160J	SN74S161J
Dice	0° C to +75° C	SN74S160X	SN74S161X
Hermetic DIP	-55° C to +125° C	SN54S160J	SN54S161J
Hermetic Flat Pak	-55° C to +125° C	SN54S160W	SN54S161W
Dice	-55° C to +125° C	SN54S160X	SN54S161X

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

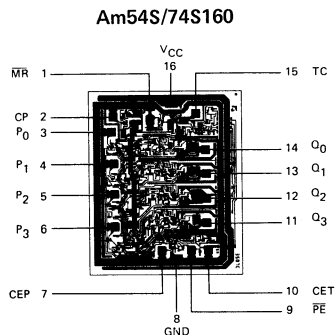
ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am74S160X, Am74S161X	T _A = 0°C to +75°C	V _{CC} = 5.0V ± 5% (COM'L)	MIN. = 4.75V	MAX. = 5.25V
Am54S160X, Am54S161X	T _A = -55°C to +125°C	V _{CC} = 5.0V ± 10% (MIL)	MIN. = 4.5V	MAX. = 5.5V

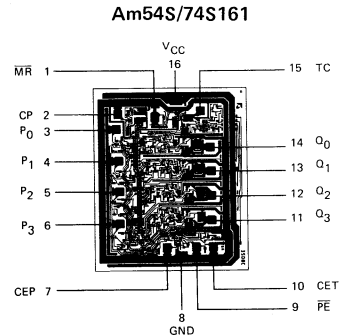
Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1mA V _{IN} = V _{IH} or V _{IL}	MIL. 2.5 COM'L 2.7	3.4 3.4		Volts
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}		0.35	0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{IL} (Note 3)	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V	P; MR; CEP		-2.0	mA
			CET		-3.0	
			PE		-4.0	
			CP		-5.0	
I _{IH} (Note 3)	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V	P; MR; CEP		50	μA
			CET		75	
			PE		100	
			CP		125	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX.	-40	-65	-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)		82	127	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
 4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 5. Outputs open; MR = 0V; all other inputs HIGH.

4

Metallization and Pad Layouts

DIE SIZE 0.078" X 0.096"



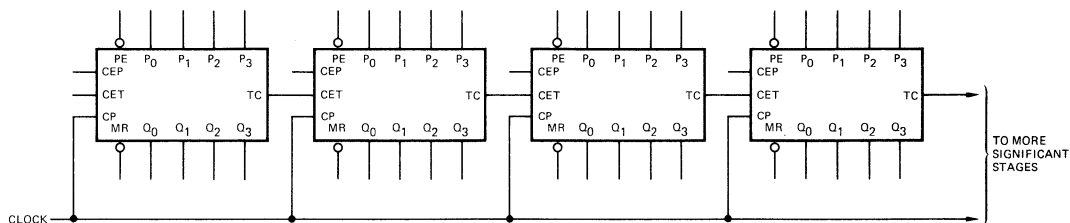
DIE SIZE 0.078" X 0.096"

SWITCHING CHARACTERISTICS (T_A = +25°)

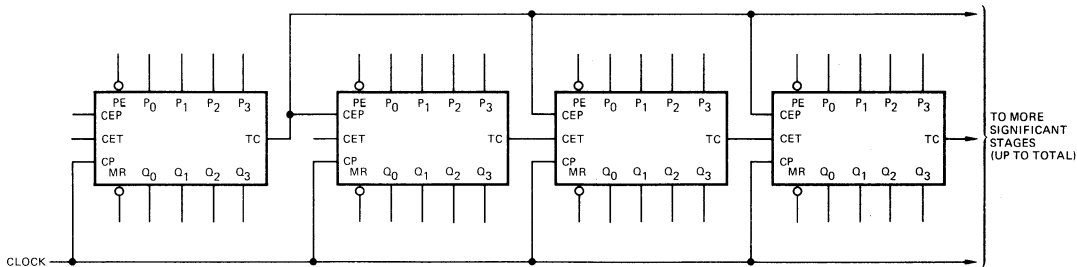
Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
f _{MAX}	Count Frequency	V _{CC} = 5.0V, C _L = 15 pF, R _L = 280Ω	70	100		MHz
t _{PLH}	Clock to Q		6	9		ns
t _{PHL}			8.5	13		
t _{PLH}	Clock to TC		12	18		ns
t _{PHL}			8	12		
t _{PLH}	CET to TC		6.5	10		ns
t _{PHL}			6.5	10		
t _{PHL}	MR to Q		14	20		ns
t _s	Recovery Time for MR (inactive)		6			ns
t _{pw}	Master Reset Pulse Width		13			ns
t _{pw}	Clock Pulse Width HIGH		6			ns
	Clock Pulse Width LOW		10			
t _s	Data to Clock		8			ns
t _h			0			
t _s	PE to Clock		16			ns
t _h			0			
t _s	CEP or CET to Clock	12			ns	
t _h		0				

APPLICATIONS

SYNCHRONOUS MULTISTAGE COUNTING USING CET INPUT ONLY



FASTER SYNCHRONOUS MULTISTAGE COUNTING USING CET AND CEP INPUTS



DEFINITION OF FUNCTIONAL TERMS

\overline{PE} Parallel Enable. When \overline{PE} is LOW, the parallel inputs, P_0 through P_3 , are enabled. When \overline{PE} is HIGH, the count function is possible.

CEP Count Enable Parallel. CEP is one of the count enable inputs that must be HIGH for the counter to count.

CET Count Enable Trickle. CET is one of the count enable inputs that must be HIGH for the counter to count. In addition, CET is included in the TC output gate and must be HIGH for TC to be HIGH.

CP Clock Pulse. Causes the required output change on the LOW-to-HIGH transition (Edge-triggered).

\overline{MR} Master Reset. When the asynchronous master reset is LOW, the Q_0 through Q_3 outputs will be LOW regardless of the other inputs.

P_0, P_1, P_2, P_3 The parallel data inputs for the four internal flip-flops.

Q_0, Q_1, Q_2, Q_3 The four parallel outputs from the counter.

TC Terminal Count. The terminal count output will be HIGH for CET HIGH and binary nine on the Am54S/74S160 or CET HIGH and binary 15 on the Am54S/74S161.

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
\overline{MR}	1	1	—	—
CP	2	2.5	—	—
P_0	3	1	—	—
P_1	4	1	—	—
P_2	5	1	—	—
P_3	6	1	—	—
CEP	7	1	—	—
GND	8	—	—	—
\overline{PE}	9	2	—	—
CET	10	1.5	—	—
Q_3	11	—	20	10
Q_2	12	—	20	10
Q_1	13	—	20	10
Q_0	14	—	20	10
TC	15	—	20	10
V_{CC}	16	—	—	—

A Schottky TTL Unit Load is defined as 50 μ A measured at 2.7V HIGH and -2.0mA measured at 0.5V LOW.

FUNCTION TABLE

INPUTS									OUTPUTS			
CP	\overline{MR}	\overline{PE}	CEP	CET	P_0	P_1	P_2	P_3	Q_0	Q_1	Q_2	Q_3
X	L	X	X	X	X	X	X	X	L	L	L	L
†	H	L	X	X	D_0	D_1	D_2	D_3	D_0	D_1	D_2	D_3
†	H	H	L	L	X	X	X	X	NC	NC	NC	NC
†	H	H	L	H	X	X	X	X	NC	NC	NC	NC
†	H	H	H	L	X	X	X	X	NC	NC	NC	NC
†	H	H	H	H	X	X	X	X	COUNT			

H = HIGH
L = LOW
X = Don't Care

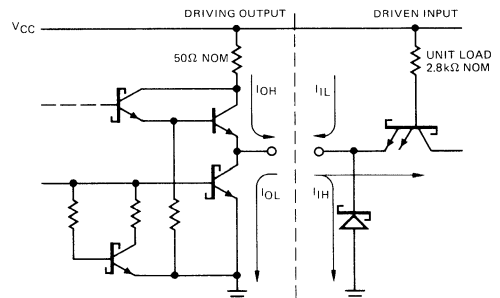
NC = No Change
 D_i may be either HIGH or LOW
† LOW-to-HIGH Transition

TERMINAL COUNT (TC) TRUTH TABLE

Am54S/74S160					Am54S/74S161					TC
CET	Q_0	Q_1	Q_2	Q_3	CET	Q_0	Q_1	Q_2	Q_3	
H	H	L	L	H	H	H	H	H	H	H
L	X	X	X	X	L	X	X	X	X	L
X	L	X	X	X	X	L	X	X	X	L
X	X	H	X	X	X	X	L	X	X	L
X	X	X	H	X	X	X	X	L	X	L
X	X	X	X	L	X	X	X	X	L	L

H = HIGH
L = LOW
X = Don't Care

SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

Am54S/74S174 • Am54S/74S175

Hex/Quadruple D-Type Flip Flops With Clear

Distinctive Characteristics

- 4-Bit and 6-Bit high-speed parallel registers.
- Common clock and common clear.

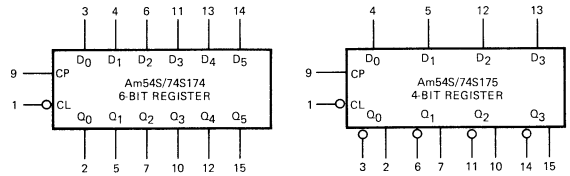
- Positive edge-triggered D flip-flops
- 100% reliability assurance testing in compliance with MIL-STD-883.

FUNCTIONAL DESCRIPTION

The Am54S/74S174 is a six-bit, high-speed register and the Am54S/74S175 is a four-bit, high-speed register built using advanced Schottky technology. The registers consist of D-type flip-flops with a buffered common clock and an asynchronous active LOW buffered clear.

When the clear is LOW, the Q outputs are LOW independent of the other inputs. Information meeting the set-up requirements of the D inputs is transferred to the Q outputs on the positive-going edge of the clock pulse.

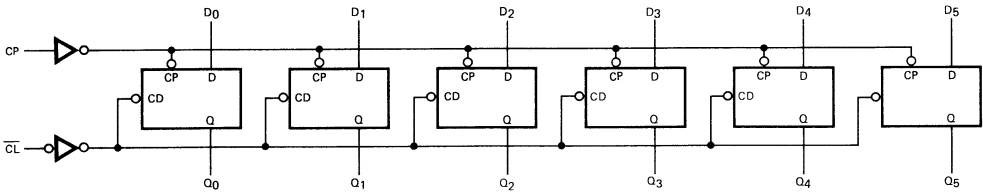
LOGIC SYMBOLS



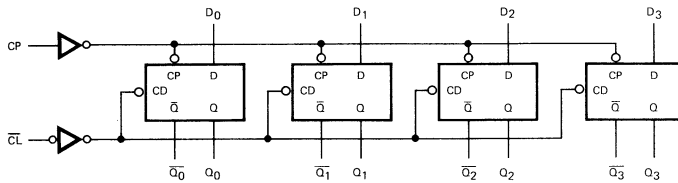
V_{CC} = Pin 16
GND = Pin 8

LOGIC DIAGRAMS

Am54S/74S174



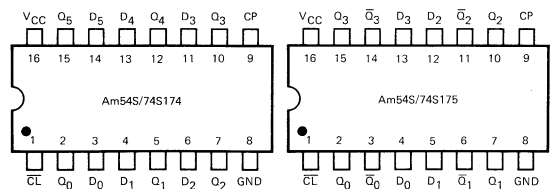
Am54S/74S175



ORDERING INFORMATION

Package Type	Temperature Range	Am54S/74S174 Order Number	Am54S/74S175 Order Number
Molded DIP	0°C to +70°C	SN74S174N	SN74S175N
Hermetic DIP	0°C to +70°C	SN74S174J	SN74S175J
Dice	0°C to +70°C	SN74S174X	SN74S175X
Hermetic DIP	-55°C to +125°C	SN54S174J	SN54S175J
Hermetic Flat Pak	-55°C to +125°C	SN54S174W	SN54S175W
Dice	-55°C to +125°C	SN54S174X	SN54S175X

CONNECTION DIAGRAMS Top Views



Note: Pin 1 is marked for orientation.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5 V to +7 V
DC Voltage Applied to Outputs for High Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +5.5 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am74S174, Am74S175 T_A = 0°C to +70°C V_{CC} = 5.0 V ±5% (COM'L) MIN. = 4.75 V MAX. = 5.25 V
 Am54S174, Am54S175 T_A = -55°C to +125°C V_{CC} = 5.0 V ±10% (MIL) MIN. = 4.5 V MAX. = 5.5 V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1 mA	74S	2.7	3.4	
		V _{IN} = V _{IH} or V _{IL}	54S	2.5	3.4	
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20 mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18 mA			-1.2	Volts
I _{IL} (Note 3)	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5 V			-2	mA
I _{IH} (Note 3)	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7 V			50	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5 V			1.0	mA
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 0.0 V	-40		-100	mA
I _{CC}	Power Supply Current (Note 5)	V _{CC} = MAX.	S174	90	144	mA
			S175	60	96	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0 V, 25°C ambient and maximum loading.
 3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
 4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 5. All outputs open and 4.5 V applied to the data and clear inputs. Measured after a momentary ground, then 4.5 V applied to the clock input.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	Clock to Output	V _{CC} = 5.0 V, C _L = 15 pF, R _L = 280 Ω		8	12	ns
t _{PHL}				11.5	17	
t _{PLH}	Clear to Output			10	15	ns
t _{PHL}				13	22	
t _{pw}	Pulse Width		Clock	7		ns
			Clear	10		
t _s	Data Set-up Time			5		ns
t _s	Set-up Time. Clear Recovery (in-active) to Clock			5		ns
t _h	Data Hold Time			3		ns
f _{MAX}	Maximum Clock Frequency			75	110	MHz

Am54S/74S174 LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
\overline{CL}	1	1	—	—
Q_0	2	—	20	10
D_0	3	1	—	—
D_1	4	1	—	—
Q_1	5	—	20	10
D_2	6	1	—	—
Q_2	7	—	20	10
GND	8	—	—	—
CP	9	1	—	—
Q_3	10	—	20	10
D_3	11	1	—	—
Q_4	12	—	20	10
D_4	13	1	—	—
D_5	14	1	—	—
Q_5	15	—	20	10
VCC	16	—	—	—

Am54S/74S175 LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
\overline{CL}	1	1	—	—
Q_0	2	—	20	10
$\overline{Q_0}$	3	—	20	10
D_0	4	1	—	—
D_1	5	1	—	—
$\overline{Q_1}$	6	—	20	10
Q_1	7	—	20	10
GND	8	—	—	—
CP	9	1	—	—
Q_2	10	—	20	10
$\overline{Q_2}$	11	—	20	10
D_2	12	1	—	—
D_3	13	1	—	—
$\overline{Q_3}$	14	—	20	10
Q_3	15	—	20	10
VCC	16	—	—	—

FUNCTION TABLE

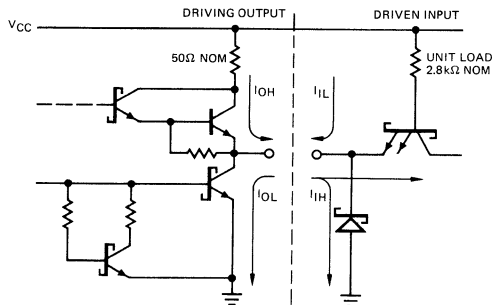
INPUTS			OUTPUTS	
Clear	Clock	D_i	Q_i	\overline{Q}_i
L	X	X	L	H
H	L	X	NC	NC
H	H	X	NC	NC
H	↑	L	L	H
H	↑	H	H	L

H = HIGH X = Don't Care
 L = LOW NC = No Change
 ↑ = LOW-to-HIGH Transition
 Note: \overline{Q}_i on Am54S/74S175 only

DEFINITION OF FUNCTIONAL TERMS

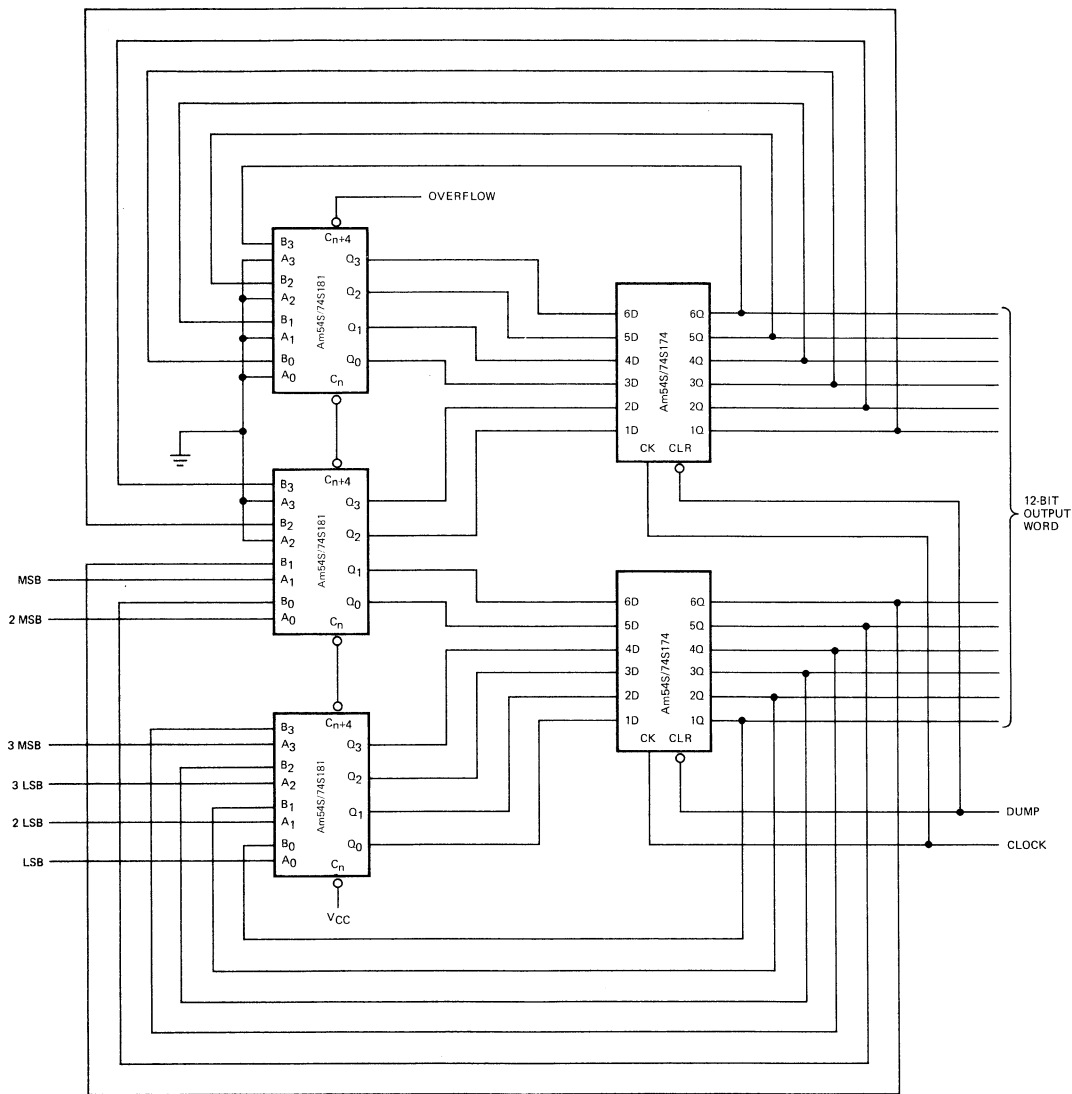
D_i The D flip-flop data inputs.
CL Clear. When the clear is LOW, the Q_i outputs are LOW, regardless of the other inputs. When the clear is HIGH, data can be entered in the register.
CP Clock pulse for the register. Enters data on the positive transition.
 Q_i The TRUE register outputs.
 \overline{Q}_i The complement register outputs.

SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

APPLICATION



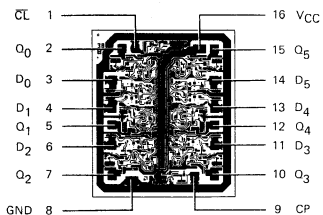
(Am54S/74S181 in ADD mode)

6-Bit Input, Integrate and Dump for Magnitude-Only Arithmetic (65 samples min. before overflow)

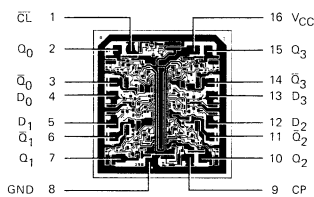
Am54S/74S174

Metallization and Pad Layouts

Am54S/74S175



DIE SIZE: 0.070" X 0.083"



DIE SIZE: 0.067" X 0.073"

Am54S/74S181

Four-Bit Arithmetic Logic Unit/Function Generator

Distinctive Characteristics

- Advanced Schottky technology
- Performs 16 arithmetic operations including add, subtract, double and compare.
- Performs all 16 possible logic operations of two variables in typically 11ns.
- Typical 4-bit add time is 11ns and carry time is 6ns.
- Full look-ahead capability for high-speed arithmetic operation on long words.
- 100% reliability assurance testing in compliance with MIL-STD-883.

FUNCTIONAL DESCRIPTION

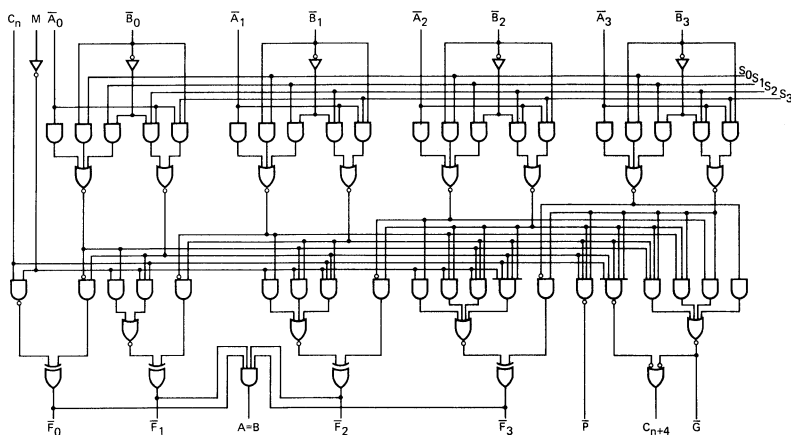
The Am54S/74S181 is a 4-bit, high-speed parallel Arithmetic Logic Unit (ALU)/Digital Function Generator. When the mode control (M) is LOW the 16 arithmetic operations are performed under the control of the four select inputs. When the mode control is HIGH the sixteen logic operations are performed on an individual bit basis between the two 4-bit parallel words under the control of the four select inputs.

An internal full look-ahead carry scheme is used for high-speed arithmetic operations and provision is made for further look-ahead by including both carry propagate (P) and carry generate (G) outputs.

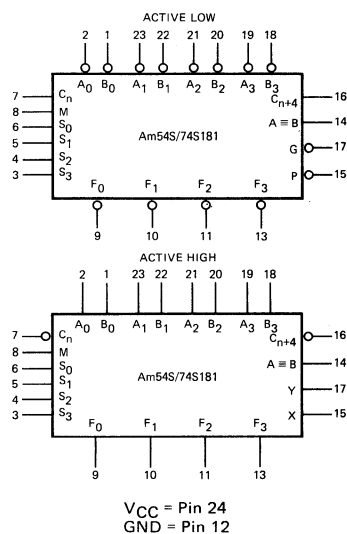
An open collector output $A = B$ is used to signal the equivalence of the two parallel words. The open collector feature allows for the equivalence function to be expanded as a wired-AND connection for larger word lengths.

In many systems, the carry output C_{n+4} is connected to the next higher C_n to provide ripple block arithmetic. The ALU can be used with either active HIGH or active LOW inputs and can be ripple expanded or full look-ahead expanded in either mode. The connection pattern is identical for either logic representation.

LOGIC DIAGRAM



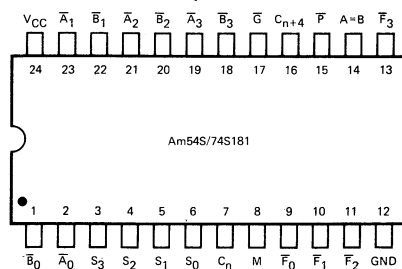
LOGIC SYMBOLS



ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	SN74S181N
Hermetic DIP	0°C to +70°C	SN74S181J
Dice	0°C to +70°C	SN74S181X
Hermetic DIP	-55°C to +125°C	SN54S181J
Hermetic Flat Pak	-55°C to +125°C	SN54S181W
Dice	-55°C to +125°C	SN54S181X

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 24 to Pin 12) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless otherwise noted)

Am74S181	T _A = 0°C to +70°C	V _{CC} = 5.0V ±5% (COM'L)	MIN. = 4.75V	MAX. = 5.25V
Am54S181	T _A = -55°C to +125°C	V _{CC} = 5.0V ±10% (MIL)	MIN. = 4.5V	MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)			Units
			Min.	Max.	Max.	
V _{OH}	Output HIGH Voltage (Except A=B Output)	V _{CC} = MIN., I _{OH} = -1mA V _{IN} = V _{IH} or V _{IL}	54S	2.5	3.4	Volts
			74S	2.7	3.4	
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{OH}	Output HIGH Current for A=B Output	V _{CC} = MIN., V _{OH} = 5.5V V _{IN} = V _{IH} or V _{IL}			250	μA
I _{IL} (Note 3)	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V	M		-2	mA
			\overline{A}_i or \overline{B}_i		-6	
			S _i		-8	
			C _n		-10	
I _{IH} (Note 3)	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V	M		50	μA
			\overline{A}_i or \overline{B}_i		150	
			S _i		200	
			C _n		250	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1	mA
I _{SC}	Output Short Circuit Current (Note 4) (Except A = B Output)	V _{CC} = MAX.	-40		-100	mA
I _{CC}	Power Supply Current (Note 5)	V _{CC} = MAX.		120	180	mA
		V _{CC} = MAX., T _A = 125°C Am54S Flat Package (W) Only			159	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
5. I_{CC} is measured under two conditions - typ. and max. apply to both.
A. S_i, M, A_i at 4.5V; all other inputs grounded; outputs open.
B. S_i, M at 4.5V; all other inputs grounded; outputs open.

SWITCHING CHARACTERISTICS ($V_{CC} = 5V$, $T_A = 25^\circ C$, $C_L = 15 \text{ pF}$, $R_L = 280\Omega$)

Parameter	From (Input)	To (Output)	Test Conditions	Min.	Typ.	Max.	Units
t_{PLH}	C_n	C_{n+4}			5	10.5	ns
t_{PHL}				7	10.5		
t_{PLH}	C_n	\overline{F}_i	M = 0V (SUM or DIFF mode)		7	12	ns
t_{PHL}				6	12		
t_{PLH}	\overline{A}_i or \overline{B}_i	\overline{G}	M = 0V, $S_0 = S_3 = 4.5V$, $S_1 = S_2 = 0V$ (SUM mode)		8	12	ns
t_{PHL}				7	12		
t_{PLH}	\overline{A}_i or \overline{B}_i	\overline{G}	M = 0V, $S_0 = S_3 = 0V$, $S_1 = S_2 = 4.5V$ (DIFF mode)		10	15	ns
t_{PHL}				10	15		
t_{PLH}	\overline{A}_i or \overline{B}_i	\overline{P}	M = 0V, $S_0 = S_3 = 4.5V$, $S_1 = S_2 = 0V$ (SUM mode)		7.5	12	ns
t_{PHL}				7.5	12		
t_{PLH}	\overline{A}_i or \overline{B}_i	\overline{P}	M = 0V, $S_0 = S_3 = 0V$, $S_1 = S_2 = 4.5V$ (DIFF mode)		10	15	ns
t_{PHL}				10.5	15		
t_{PLH}	\overline{A}_i or \overline{B}_i	$F_j (j \geq i)$	M = 0V, $S_0 = S_3 = 4.5V$, $S_1 = S_2 = 0V$ (SUM mode)		10	16.5	ns
t_{PHL}				7	16.5		
t_{PLH}	\overline{A}_i or \overline{B}_i	$F_j (j \geq i)$	M = 0V, $S_0 = S_3 = 0V$, $S_1 = S_2 = 4.5V$ (DIFF mode)		12	20	ns
t_{PHL}				9	22		
t_{PLH}	\overline{A}_i or \overline{B}_i	\overline{F}_{i+1}	M = 0V, $S_0 = S_3 = 4.5V$, $S_1 = S_2 = 0V$ (SUM mode)		11	16.5	ns
t_{PHL}				11	16.5		
t_{PLH}	\overline{A}_i or \overline{B}_i	\overline{F}_{i+1}	M = 0V, $S_0 = S_3 = 0V$, $S_1 = S_2 = 4.5V$ (DIFF mode)		14	20	ns
t_{PHL}				14	22		
t_{PLH}	\overline{A}_i or \overline{B}_i	\overline{F}_i	M = 4.5V (LOGIC mode)		12	20	ns
t_{PHL}				9	22		
t_{PLH}	\overline{A}_i or \overline{B}_i	C_{n+4}	M = 0V, $S_0 = S_3 = 4.5V$, $S_1 = S_2 = 0V$ (SUM mode)		12.5	18.5	ns
t_{PHL}				12.5	18.5		
t_{PLH}	\overline{A}_i or \overline{B}_i	C_{n+4}	M = 0V, $S_0 = S_3 = 0V$, $S_1 = S_2 = 4.5V$ (DIFF mode)		14	23	ns
t_{PHL}				15	23		
t_{PLH}	\overline{A}_i or \overline{B}_i	A = B	M = 0V, $S_0 = S_3 = 0V$, $S_1 = S_2 = 4.5V$ (DIFF mode)		15	23	ns
t_{PHL}				19	30		

OPERATION TABLE

CONTROL INPUTS				ACTIVE LOW INPUTS AND OUTPUTS		ACTIVE HIGH INPUTS AND OUTPUTS	
S_0	S_1	S_2	S_3	Arithmetic (M = L, $C_n = L$)	Logic (M = H)	Arithmetic (M = L, $\overline{C}_n = H$)	Logic (M = H)
L	L	L	L	A minus 1	\overline{A}	A	\overline{A}
H	L	L	L	AB minus 1	\overline{AB}	A + B	$\overline{A + B}$
L	H	L	L	\overline{AB} minus 1	$\overline{A + B}$	A + \overline{B}	\overline{AB}
H	H	L	L	minus 1 (2's comp.)	Logic '1'	minus 1 (2's comp.)	Logic '0'
L	L	H	L	A plus [A + \overline{B}]	$\overline{A + B}$	A plus \overline{AB}	\overline{AB}
H	L	H	L	AB plus [A + \overline{B}]	\overline{B}	\overline{AB} plus [A + B]	\overline{B}
L	H	H	L	A minus B minus 1	$\overline{A \oplus B}$	A minus B minus 1	$A \oplus B$
H	H	H	L	A + \overline{B}	$\overline{A + B}$	\overline{AB} minus 1	\overline{AB}
L	L	L	H	A plus [A + B]	\overline{AB}	A plus AB	$\overline{A + B}$
H	L	L	H	A plus B	$\overline{A \oplus B}$	A plus B	$\overline{A \oplus B}$
L	H	L	H	\overline{AB} plus [A + B]	B	AB plus [A + \overline{B}]	B
H	H	L	H	A + B	A + B	AB minus 1	AB
L	L	H	H	A plus A (2 x A)	Logic '0'	A plus A (2 x A)	Logic '1'
H	L	H	H	A plus AB	\overline{AB}	A plus [A + B]	$\overline{A + B}$
L	H	H	H	A plus \overline{AB}	AB	A plus [A + \overline{B}]	A + B
H	H	H	H	A	A	A minus 1	A

L = LOW Voltage Level
H = HIGH Voltage Level

DEFINITION OF FUNCTIONAL TERMS

$\bar{A}_0, \bar{A}_1, \bar{A}_2, \bar{A}_3$ The A data inputs.

$\bar{B}_0, \bar{B}_1, \bar{B}_2, \bar{B}_3$ The B data inputs.

S_0, S_1, S_2, S_3 The control inputs used to determine the arithmetic or logic function performed.

$\bar{F}_0, \bar{F}_1, \bar{F}_2, \bar{F}_3$ The data outputs of the ALU.

M The mode control inputs used to select either the arithmetic or logic operations.

C_n The carry-in input of the ALU.

C_{n+4} The carry-look-ahead output of the four-bit input field.

\bar{G} The carry-generate output for use in multi-level look-ahead schemes.

\bar{P} The carry-propagate output for use in multi-level look-ahead schemes.

A = B The open collector comparator output that can be used to determine equivalence. This output is HIGH whenever the four \bar{F} outputs are HIGH.

USER NOTES

1. Throughout this data sheet, the active LOW input and output terminology has been used. For the active HIGH definition, the nomenclature shown under the active HIGH logic symbol should be substituted.
2. Arithmetic operations are performed on a word basis.
3. Logic operations are performed on a bit basis.
4. Arithmetic in 1's complement notation requires an end around carry.
5. Subtraction in 2's complement notation requires a carry in ($C_n = \text{HIGH}$) for the active LOW case and ($\bar{C}_n = \text{LOW}$) for the active HIGH case.
6. The **A = B** output only indicates that the four \bar{F} outputs are all HIGH.

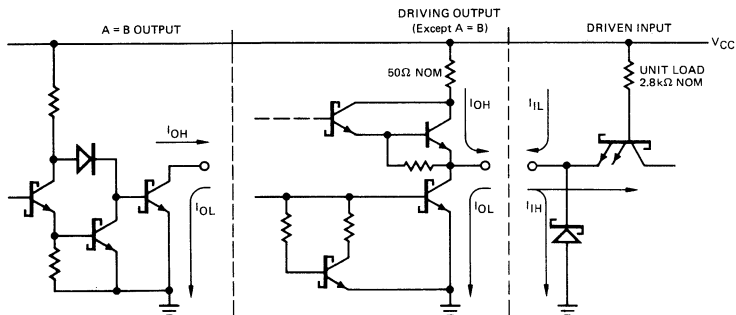
LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Output Drive	
			Output HIGH	Output LOW
\bar{B}_0	1	3	—	—
\bar{A}_0	2	3	—	—
S_3	3	4	—	—
S_2	4	4	—	—
S_1	5	4	—	—
S_0	6	4	—	—
C_n	7	5	—	—
M	8	1	—	—
\bar{F}_0	9	—	20	10
\bar{F}_1	10	—	20	10
\bar{F}_2	11	—	20	10
GND	12	—	—	—
\bar{F}_3	13	—	20	10
A = B	14	—	O/C	10
\bar{P}	15	—	20	10
C_{n+4}	16	—	20	10
\bar{G}	17	—	20	10
\bar{B}_3	18	3	—	—
\bar{A}_3	19	3	—	—
\bar{B}_2	20	3	—	—
\bar{A}_2	21	3	—	—
\bar{B}_1	22	3	—	—
\bar{A}_1	23	3	—	—
VCC	24	—	—	—

O/C = Open Collector

A Schottky unit load is defined as $50\mu\text{A}$ measured at 2.7V HIGH and -2.0 mA measured at 0.5V LOW.

SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

SUM MODE TEST TABLE

FUNCTION INPUTS: $S_0 = S_3 = 4.5V, S_1 = S_2 = M = 0V$

Parameter	Input Under Test	Other Input Same Bit		Other Data Inputs		Output Under Test	Output Waveform
		Apply 4.5V	Apply 0V	Apply 4.5V	Apply 0V		
t_{PLH} t_{PHL}	\bar{A}_i	\bar{B}_i	None	Remaining \bar{A} and \bar{B}	C_n	$\bar{F}_i(i \geq 1)$	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	Remaining \bar{A} and \bar{B}	C_n	$\bar{F}_i(i \geq 1)$	In-Phase
t_{PLH} t_{PHL}	\bar{A}_i	\bar{B}_i	None	C_n	Remaining \bar{A} and \bar{B}	\bar{F}_{i+1}	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	C_n	Remaining \bar{A} and \bar{B}	\bar{F}_{i+1}	In-Phase
t_{PLH} t_{PHL}	\bar{A}_i	\bar{B}_i	None	None	Remaining \bar{A} and \bar{B}, C_n	\bar{P}	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	None	Remaining \bar{A} and \bar{B}, C_n	\bar{P}	In-Phase
t_{PLH} t_{PHL}	\bar{A}_i	None	\bar{B}_i	Remaining \bar{B}	Remaining \bar{A}, C_n	\bar{G}	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	None	\bar{A}_i	Remaining \bar{B}	Remaining \bar{A}, C_n	\bar{G}	In-Phase
t_{PLH} t_{PHL}	\bar{A}_i	None	\bar{B}_i	Remaining \bar{B}	Remaining \bar{A}, C_n	C_n+4	Out-of-Phase
t_{PLH} t_{PHL}	\bar{B}_i	None	\bar{A}_i	Remaining \bar{B}	Remaining \bar{A}, C_n	C_n+4	Out-of-Phase
t_{PLH} t_{PHL}	C_n	None	None	All \bar{A}	All \bar{B}	Any \bar{F} or C_n+4	In-Phase

DIFF MODE TEST TABLE

FUNCTION INPUTS: $S_1 = S_2 = 4.5V, S_0 = S_3 = M = 0V$

Parameter	Under Test	Other Input Same Bit		Other Data Inputs		Output Under Test	Output Waveform
		Apply 4.5V	Apply 0V	Apply 4.5V	Apply 0V		
t_{PLH} t_{PHL}	\bar{A}_i	None	\bar{B}_i	Remaining \bar{A}	Remaining \bar{B}, C_n	$\bar{F}_i(i \geq 1)$	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	Remaining \bar{A}	Remaining \bar{B}, C_n	$\bar{F}_i(i \geq 1)$	Out-of-Phase
t_{PLH} t_{PHL}	\bar{A}_i	None	\bar{B}_i	Remaining \bar{B}, C_n	Remaining \bar{A}	\bar{F}_{i+1}	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	Remaining \bar{B}, C_n	Remaining \bar{A}	\bar{F}_{i+1}	Out-of-Phase
t_{PLH} t_{PHL}	\bar{A}_i	None	\bar{B}_i	None	Remaining \bar{A} and \bar{B}, C_n	\bar{P}	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	None	Remaining \bar{A} and \bar{B}, C_n	\bar{P}	Out-of-Phase
t_{PLH} t_{PHL}	\bar{A}_i	\bar{B}_i	None	None	Remaining \bar{A} and \bar{B}, C_n	\bar{G}	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	None	\bar{A}_i	None	Remaining \bar{A} and \bar{B}, C_n	\bar{G}	Out-of-Phase
t_{PLH} t_{PHL}	\bar{A}_i	None	\bar{B}_i	Remaining \bar{A}	Remaining \bar{B}, C_n	$A = B$	In-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	Remaining \bar{A}	Remaining \bar{B}, C_n	$A = B$	Out-of-Phase
t_{PLH} t_{PHL}	\bar{A}_i	\bar{B}_i	None	None	Remaining \bar{A} and \bar{B}, C_n	C_n+4	Out-of-Phase
t_{PLH} t_{PHL}	\bar{B}_i	None	\bar{A}_i	None	Remaining \bar{A} and \bar{B}, C_n	C_n+4	In-Phase
t_{PLH} t_{PHL}	C_n	None	None	All \bar{A} and \bar{B}	None	Any \bar{F} or C_n+4	In-Phase

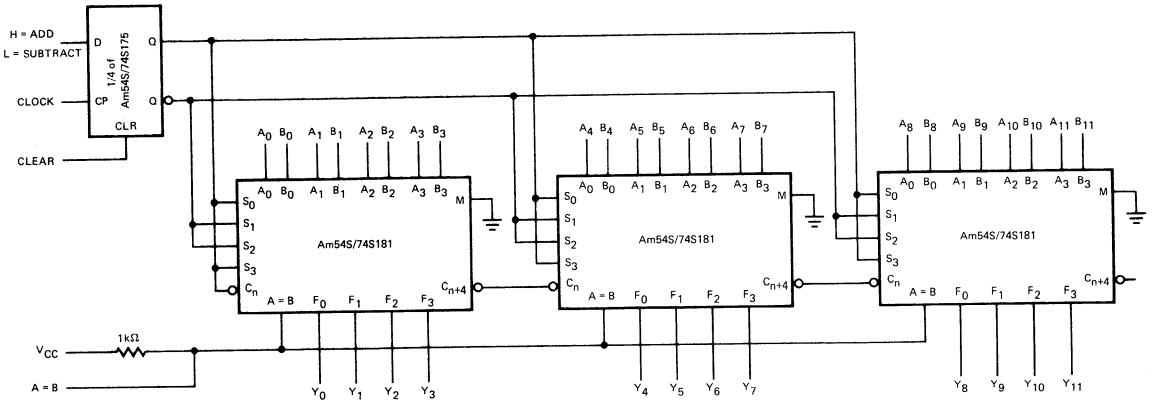
LOGIC MODE TEST TABLE

FUNCTION INPUTS: $S_1 = S_2 = M = 4.5V, S_0 = S_3 = 0V$

Parameter	Input Under Test	Other Input Same Bit		Other Data Inputs		Output Under Test	Output Waveform
		Apply 4.5V	Apply 0V	Apply 4.5V	Apply 0V		
t_{PLH} t_{PHL}	\bar{A}_i	\bar{B}_i	None	None	Remaining \bar{A} and \bar{B}, C_n	\bar{F}_i	Out-of-Phase
t_{PLH} t_{PHL}	\bar{B}_i	\bar{A}_i	None	None	Remaining \bar{A} and \bar{B}, C_n	\bar{F}_i	Out-of-Phase

APPLICATIONS

12-Bit Adder /Subtractor (2's Complement)

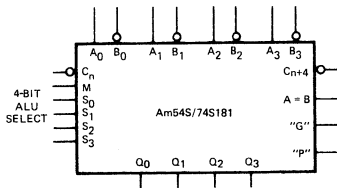


Function Table

A = Active HIGH B = Active LOW

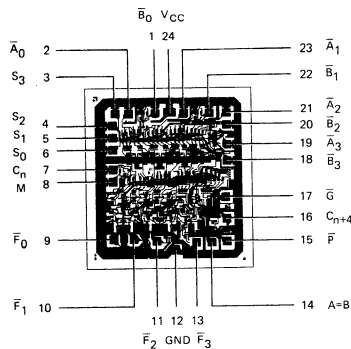
S ₀	S ₁	S ₂	S ₃	Arithmetic (M = L, $\bar{C}_n = H$)	Logic (M = H)
L	L	L	L	A	\bar{A}
H	L	L	L	A + \bar{B}	$\bar{A}B$
L	H	L	L	A + B	$\bar{A}\bar{B}$
H	H	L	L	minus 1 (2's comp.)	Logic '0'
L	L	H	L	A plus AB	AB
H	L	H	L	AB plus [A + \bar{B}]	B
L	H	H	L	A plus B	$A \oplus B$
H	H	H	L	AB minus 1	AB
L	L	L	H	A plus $\bar{A}\bar{B}$	$\bar{A} + \bar{B}$
H	L	L	H	A minus B minus 1	$A \oplus B$
L	H	L	H	$\bar{A}\bar{B}$ plus [A + B]	\bar{B}
H	H	L	H	$\bar{A}\bar{B}$ minus 1	$\bar{A}\bar{B}$
L	L	H	H	A plus A (2 x A)	Logic '1'
H	L	H	H	A plus [A + \bar{B}]	A + B
L	H	H	H	A plus [A + B]	A + \bar{B}
H	H	H	H	A minus 1	A

If one input is defined active-HIGH and the second input is defined active-LOW, the sixteen arithmetic and logic functions of the ALU are reordered as shown in the function table.



L = Low Voltage Level
H = High Voltage Level

Metallization and Pad Layout



DIE SIZE: = 0.083" X 0.091"



Am54S/74S194 • Am54S/74S195

Four-Bit High-Speed Shift Registers

Distinctive Characteristics

- Parallel load or shift right with \overline{JK} inputs on Am54S/74S195.
- Shift left, right, parallel load or do nothing on Am54S/74S194

- Fully synchronous shifting and parallel loading
- Buffered common clock
- Buffered common active-LOW clear
- 100% reliability assurance testing in compliance with MIL-STD-883

FUNCTIONAL DESCRIPTION

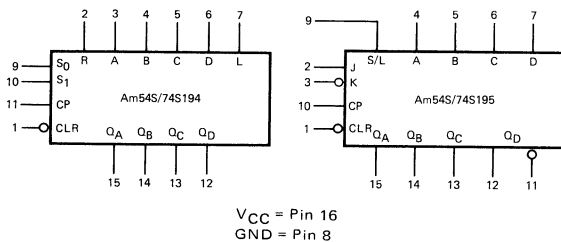
The Am54S/74S194 and Am54S/74S195 are 4-bit registers that exhibit fully synchronous operation in all operating modes. The Am54S/74S195 can either parallel load all four register bits via the parallel inputs (A, B, C, D) or shift each of the four register bits right one place. The shifting or parallel loading is under control of the shift/load input (S/L). When the shift/load input is LOW, data is loaded from the parallel data inputs; when the shift/load input is HIGH, data is loaded from the register bits on the left. The first bit, Q_A , is loaded via the J and K inputs in the shift mode.

The Am54S/74S194 operates in four modes under control of the two select inputs, S_0 and S_1 . The four modes are parallel load (data comes from the parallel inputs), shift right (data comes from the flip-flop to the left, with the Q_A bit input from R),

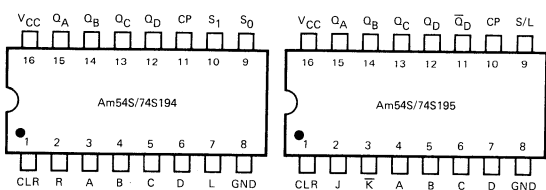
shift left (data comes from the flip-flop to the right, with the Q_D input from L), and hold or do nothing (each flip-flop receives data from its own output).

For both devices the outputs change state synchronously following a LOW-to-HIGH transition on the clock input, CP. Both devices have an active-LOW asynchronous clear (CLR) which forces all outputs to the LOW state ($\overline{Q_D}$ HIGH) independent of any other inputs. All control inputs are buffered to present only one Schottky TTL load to the system, and all outputs can drive 10 Schottky loads in the LOW state and 20 in the HIGH state. Because all the flip-flops are D-type they do not catch 0's or 1's, and the only requirements on any inputs is that they meet the short set-up and hold time intervals with respect to the clock LOW-to-HIGH transition.

LOGIC SYMBOLS



CONNECTION DIAGRAMS Top Views



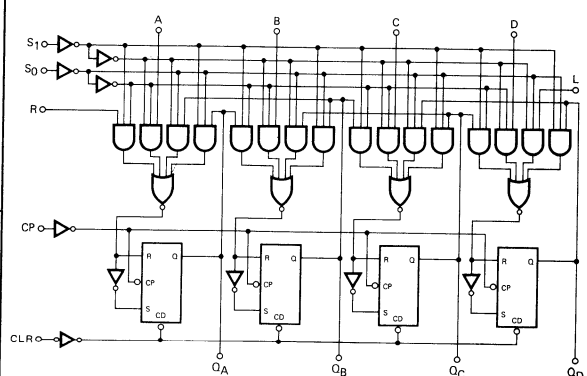
Note: Pin 1 is marked for orientation.

ORDERING INFORMATION

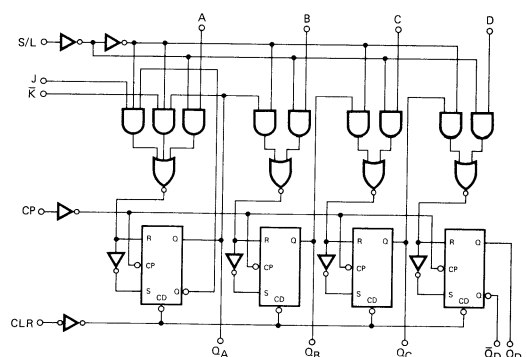
Package Type	Temperature Range	Am54S/74S194 Order Number	Am54S/74S195 Order Number
Molded DIP	0°C to +70°C	SN74S194N	SN74S195N
Hermetic DIP	0°C to +70°C	SN74S194J	SN74S195J
Dice	0°C to +70°C	SN74S194X	SN74S195X
Hermetic DIP	-55°C to +125°C	SN54S194J	SN54S195J
Hermetic Flat Pak	-55°C to +125°C	SN54S194W	SN54S195W
Dice	-55°C to +125°C	SN54S194X	SN54S195X

LOGIC DIAGRAMS

Am54S/74S194



Am54S/74S195



MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am74S194, Am74S195	T _A = 0°C to +70°C	V _{CC} = 5.0 V ± 5% (COM'L)	MIN. = 4.75 V	MAX. = 5.25 V
Am54S194, Am54S195	T _A = -55°C to +125°C	V _{CC} = 5.0 V ± 10% (MIL)	MIN. = 4.5 V	MAX. = 5.5 V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1 mA V _{IN} = V _{IH} or V _{IL}	Am74 2.7 Am54 2.5	3.4 3.4		Volts
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20 mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18 mA			-1.2	Volts
I _{IL} (Note 3)	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5 V			-2	mA
I _{IH} (Note 3)	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7 V			50	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5 V			1	mA
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX.	-40		-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX.	S194 (Note 5 & 7)	85	135	mA
			54S195 (Note 6)	70	99	
			74S195 (Note 6)	70	109	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
5. Outputs open. Inputs A, B, C, D grounded. Inputs S₀, S₁, Clear, L, R, at 4.5 V. Measured after a momentary ground, then 4.5 V applied to clock.
6. Outputs open. S/L grounded. A, B, C, D, J, K at 4.5 V. Measured after applying a momentary ground then 4.5 V to the clear followed by ground then 4.5 V to clock.
7. For T_A = 125°C; I_{CC} MAX. = 110mA for Am54S194W.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units	
t _{PLH}	Clock to Output	V _{CC} = 5.0 V, C _L = 15 pF, R _L = 280 Ω	4	8	12	ns	
t _{PHL}	Clock to Output		4	11	16.5	ns	
t _{PHL}	Clear to Output			12.5	18.5	ns	
t _{pw}	Clock Pulse Width		7			ns	
t _{pw}	Clear Pulse Width		12			ns	
t _s	Mode Control Set-up Time		11			ns	
t _s	Data Input Set-up Time		5			ns	
t _s	Clear Recovery to Clock		9			ns	
t _h	Data Hold Time		3			ns	
t _R	Shift/Load Release Time Am54S/74S195					6	ns
f _{MAX.}	Maximum Clock Frequency			70	105		MHz

DEFINITION OF FUNCTIONAL TERMS

J, \bar{K} The logic inputs used for controlling the Q_A flip-flop of the Am54S/74S195 register when S/L is HIGH.

CLR Clear. The asynchronous master reset input.

CP Clock pulse for the register. Enters data on the LOW-to-HIGH transition.

S/L Shift/Load. The input for selection of parallel or serial shifting for the Am54S/74S195 register. S/L LOW selects parallel entry.

S₀, S₁ The mode select inputs of the Am54S/74S194.

A, B, C, D The four parallel data inputs for the register.

R The serial input to the Q_A flip-flop of the Am54S/74S194 in the right shift mode.

L The serial input to the Q_D flip-flop of the Am54S/74S194 in the left shift mode.

Q_A, Q_B, Q_C, Q_D The four true outputs of the register.

\bar{Q}_D The complement output of the Q_D flip-flop. (Am54S/74S195 only).

LOADING RULES (In Unit Loads)

Am54S/74S195	Am54S/74S194	Input/Output	Pin No.'s	Input Unit Load	Output HIGH	Fan-out Output LOW
CLR	CLR		1	1	—	—
J	R		2	1	—	—
\bar{K}	A		3	1	—	—
A	B		4	1	—	—
B	C		5	1	—	—
C	D		6	1	—	—
D	L		7	1	—	—
GND	GND		8	—	—	—
Shift/Load	S ₀		9	1	—	—
CP	S ₁		10	1	—	—
\bar{Q}_D	—		11	—	20	10
—	CP		11	1	—	—
Q _D	Q _D		12	—	20	10
Q _C	Q _C		13	—	20	10
Q _B	Q _B		14	—	20	10
Q _A	Q _A		15	—	20	10
V _{CC}	V _{CC}		16	—	—	—

FUNCTION TABLE
Am54S/74S194

FUNCTION	INPUTS							OUTPUTS						
	Clear	Mode		Clock	Serial		Parallel			Q _A	Q _B	Q _C	Q _D	
		S ₁	S ₀		Left	Right	A	B	C					D
Clear	L	X	X	X	X	X	X	X	X	X	L	L	L	L
No Change	H	X	X	L	X	X	X	X	X	X	NC	NC	NC	NC
	H	X	X	H	X	X	X	X	X	X	NC	NC	NC	NC
Parallel Load	H	H	H	†	X	X	D ₀	D ₁	D ₂	D ₃	D ₀	D ₁	D ₂	D ₃
Shift Right	H	L	H	†	X	L	X	X	X	X	L	Q _A	Q _B	Q _C
	H	L	H	†	X	H	X	X	X	X	H	Q _A	Q _B	Q _C
Shift Left	H	H	L	†	L	X	X	X	X	X	Q _B	Q _C	Q _D	L
	H	H	L	†	H	X	X	X	X	X	Q _B	Q _C	Q _D	H
Hold	H	L	L	X	X	X	X	X	X	X	NC	NC	NC	NC

H = HIGH
L = LOW
† = LOW-to-HIGH transition.
D_i = May be a HIGH or a LOW and the respective output will assume the same state.

X = Don't Care
NC = No Change

FUNCTION TABLE
Am54S/74S195

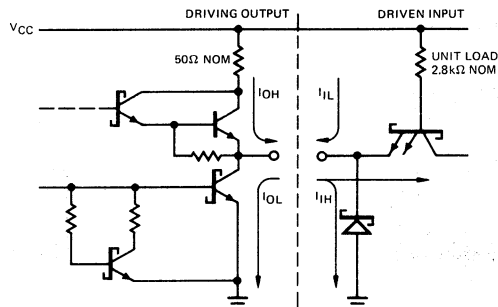
FUNCTION	INPUTS							OUTPUTS							
	Clear	Shift/Load	Clock	Serial		Parallel			Q _A	Q _B	Q _C	Q _D	\bar{Q}_D		
				J	\bar{K}	A	B	C						D	
L	X	X	X	X	X	X	X	X	X	X	L	L	L	L	H
H	X	L	X	X	X	X	X	X	X	X	NC	NC	NC	NC	NC
H	X	H	X	X	X	X	X	X	X	X	NC	NC	NC	NC	NC
H	L	†	X	X	D ₀	D ₁	D ₂	D ₃	D ₀	D ₁	D ₂	D ₃	D ₃	\bar{D}_3	
H	H	†	L	H	X	X	X	X	X	X	Q _A	Q _A	Q _B	Q _C	Q _C
H	H	†	L	L	X	X	X	X	X	X	L	Q _A	Q _B	Q _C	Q _C
H	H	†	H	H	X	X	X	X	X	X	H	Q _A	Q _B	Q _C	Q _C
H	H	†	H	L	X	X	X	X	X	X	Q _A	Q _A	Q _B	Q _C	Q _C

H = HIGH
L = LOW
† = LOW-to-HIGH transition.
D_i = May be a HIGH or a LOW and the respective output will assume the same state.

X = Don't Care
NC = No Change

Notes: 1. If the J and \bar{K} inputs are tied together, the common line becomes a D-type input to the first bit in the shift mode.
2. Linear feedback shift counters can be made by connecting the Q_D and \bar{Q}_D outputs to the K and J inputs, respectively.

SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS

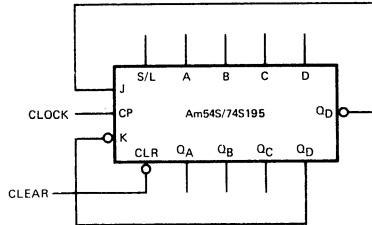


Note: Actual current flow direction shown

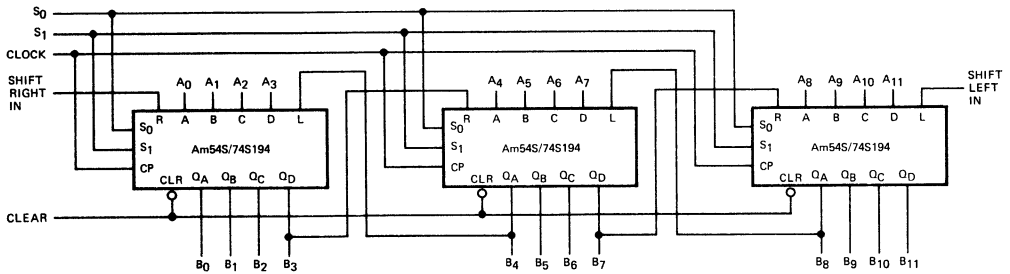
APPLICATIONS

HIGH-SPEED MOD 15 LINEAR FEEDBACK SHIFT REGISTER

Sequence is 0, 1, 2, 5, 10, 4, 9, 3, 6, 13, 11, 7, 14, 12, 8, 0 (15 is non-self correcting; use clear to initialize)

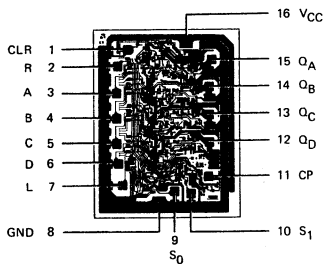


12-BIT SHIFT-LEFT, SHIFT-RIGHT, PARALLEL-LOAD REGISTER



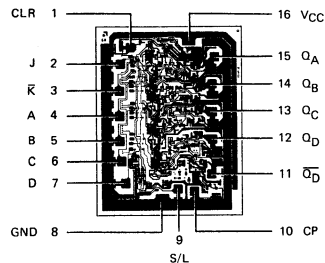
Metallization and Pad Layouts

Am54S/74S194



DIE SIZE 0.072" X 0.093"

Am54S/74S195



DIE SIZE 0.072" X 0.093"

Am54S/74S240 • Am54S/74S241 Am54S/74S242 • Am54S/74S243 Am54S/74S244

Octal Buffers/Line Drivers/Line Receivers With Three-State Outputs

DISTINCTIVE CHARACTERISTICS

- Three-state outputs drive bus lines directly
- Advanced Schottky processing
- Hysteresis at inputs improve noise margin
- PNP inputs reduce D.C. loading on bus lines
- V_{OL} of 0.55V at 64mA for Am74S; 48mA for Am54S
- Data-to-output propagation delay times:
Inverting – 7.0ns MAX
Non-inverting – 9.0ns MAX
- Enable-to-output – 15.0ns MAX
- 100% reliability assurance testing in compliance with MIL-STD-883
- 20 pin hermetic and molded DIP packages for Am54S/74S240, Am54S/74S241, and Am54S/74S244

FUNCTIONAL DESCRIPTION

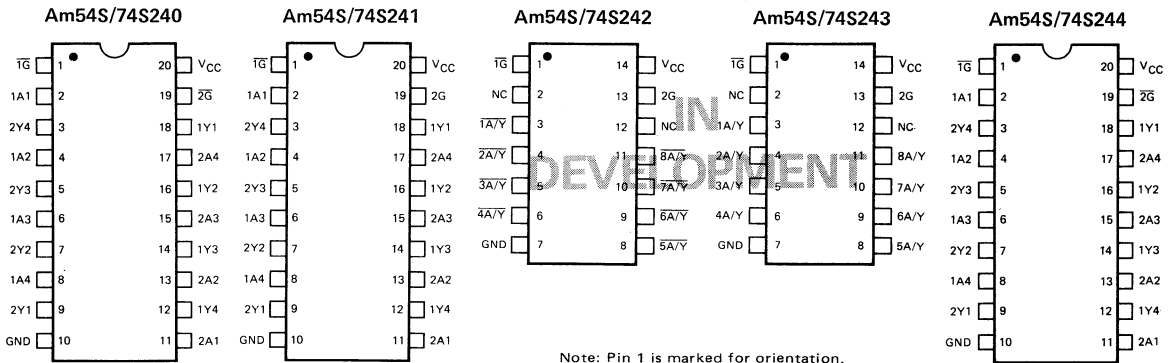
These buffers/line drivers, used as memory-address drivers, clock drivers, and bus oriented transmitters/receivers, provide improved PC board density. The outputs of the commercial temperature range versions have 64mA sink and 15mA source capability, which can be used to drive terminated lines down to 133Ω. The outputs of the military temperature range versions have 48mA sink and 12mA source current capability.

Featuring 0.2V minimum guaranteed hysteresis at each low-current PNP data input, they provide improved noise rejection and high-fan-out outputs to restore Schottky TTL levels completely.

The Am54S/74S240, Am54S/74S241 and Am54S/74S244 have four buffers which are enabled from one common line, and the other four buffers are enabled from another common line. The Am54S/74S240 is inverting, while the Am54S/74S241 and Am54S/74S244 present true data at the outputs.

The Am54S/74S242 and Am54S/74S243 have the two 4-line data paths connected input-to-output on both sides to form an asynchronous transceiver/buffer with complementing enable inputs. The Am54S/74S242 is inverting, while the Am54S/74S243 presents non-inverting data at the outputs.

CONNECTION DIAGRAMS Top Views

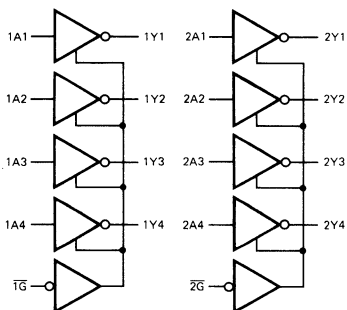


ORDERING INFORMATION

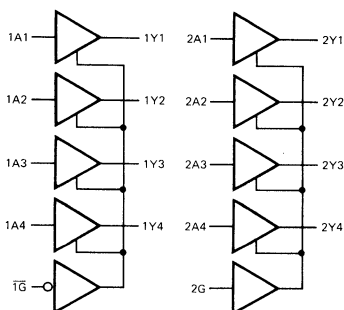
Package Type	Temperature Range	Order Number				
		Am54S/74S240	Am54S/74S241	Am54S/74S242	Am54S/74S243	Am54S/74S244
Hermetic	-55°C to +125°C	SN54S240J	SN54S241J	SN54S242J	SN54S243J	SN54S244J
Dice	-55°C to +125°C	AM54S240X	AM54S241X	AM54S242X	AM54S243X	AM54S244X
Hermetic	0°C to +70°C	SN74S240J	SN74S241J	SN74S242J	SN74S243J	SN74S244J
Molded	0°C to +70°C	SN74S240N	SN74S241N			SN74S244N
Dice	0°C to +70°C	AM74S240X	AM74S241X	AM74S242X	AM74S243X	AM74S244X

LOGIC DIAGRAMS

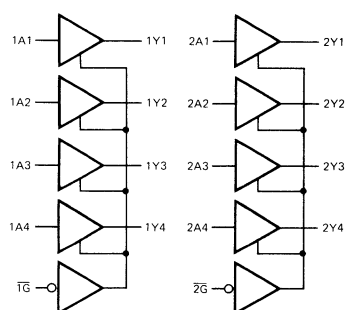
Am54S/74S240



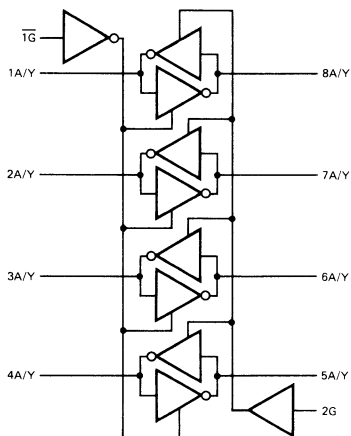
Am54S/74S241



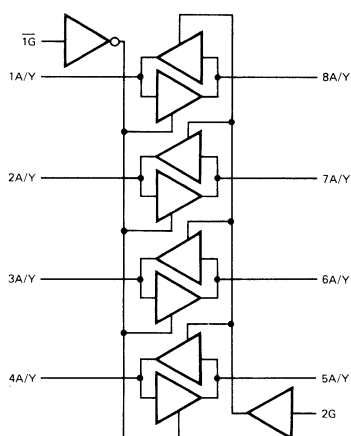
Am54S/74S244



Am54S/74S242



Am54S/74S243



Note: All gates have input hysteresis.

4

MAXIMUM RATINGS above which the useful life may be impaired

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential	-0.5V to +7.0V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +7.0V
DC Output Current	150mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Noted:

Am54S240/S241/S242/S243/S244 (MIL)

 $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC}(\text{MIN.}) = 4.50\text{V}$ $V_{CC}(\text{MAX.}) = 5.50\text{V}$

Am74S240/S241/S242/S243/S244 (COM'L)

 $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ $V_{CC}(\text{MIN.}) = 4.75\text{V}$ $V_{CC}(\text{MAX.}) = 5.25\text{V}$

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

Parameters	Description	Test Conditions (Note 1)	Typ. (Note 2)			Units		
			Min.	Max.	Max.			
V_{IH}	High-Level Input Voltage		2.0			Volts		
V_{IL}	Low-Level Input Voltage				0.8	Volts		
V_{IK}	Input Clamp Voltage	$V_{CC} = \text{MIN.}, I_I = -18\text{mA}$			-1.2	Volts		
	Hysteresis ($V_{T+} - V_{T-}$)	$V_{CC} = \text{MIN.}$	0.2	0.4		Volts		
V_{OH}	High-Level Output Voltage	$V_{CC} = \text{MIN.}, V_{IL} = 0.8\text{V}$ $I_{OH} = -3.0\text{mA}$	2.4	3.4		Volts		
		$V_{CC} = \text{MIN.}, V_{IL} = 0.5\text{V}$	MIL, $I_{OH} = -12\text{mA}$ COM'L, $I_{OH} = -15\text{mA}$	2.0				
V_{OL}	Low-Level Output Voltage	$V_{CC} = \text{MIN.}, V_{IL} = 0.8\text{V}$			0.55	Volts		
		MIL, $I_{OL} = 48\text{mA}$ COM'L, $I_{OL} = 64\text{mA}$			0.55			
I_{OZH}	Off-State Output Current, High Level Voltage Applied	$V_{CC} = \text{MAX.}, V_{IH} = 2.0\text{V}$			50	μA		
I_{OZL}	Off-State Output Current, Low-Level Voltage Applied	$V_{IL} = 0.8\text{V}$			-50			
I_I	Input Current at Maximum Input Voltage	$V_{CC} = \text{MAX.}, V_I = 5.5\text{V}$			1.0	mA		
I_{IH}	High-Level Input Current, Any Input	$V_{CC} = \text{MAX.}, V_{IH} = 2.7\text{V}$			50	μA		
I_{IL}	Low-Level Input Current	Any A	$V_{CC} = \text{MAX.}, V_{IL} = 0.5\text{V}$		-400	μA		
		Any G			-2.0	mA		
I_{OS}	Short-Circuit Output Current (Note 3)	$V_{CC} = \text{MAX.}$	-50		-225	mA		
I_{CC}	Supply Current	Am54S/74S240 Am54S/74S242	$V_{CC} = \text{MAX.}$ Outputs open	All Outputs HIGH	MIL	80	123	mA
				All Outputs LOW	COM'L	80	135	
					MIL	100	145	
				Outputs at Hi-Z	COM'L	100	150	
					MIL	100	145	
				COM'L	100	150		
		Am54S/74S241 Am54S/74S243 Am54S/74S244	$V_{CC} = \text{MAX.}$ Outputs open	All Outputs HIGH	MIL	95	147	mA
				All Outputs LOW	COM'L	95	160	
					MIL	120	170	
				Outputs at Hi-Z	COM'L	120	180	
					MIL	120	170	
				COM'L	120	180		

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under recommended operating conditions.

2. All typical values are $V_{CC} = 5.0\text{V}$, $T_A = 25^\circ\text{C}$.

3. Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

SWITCHING CHARACTERISTICS ($V_{CC} = 5\text{V}$, $T_A = 25^\circ\text{C}$)

Am54S/74S240

Am54S/74S241

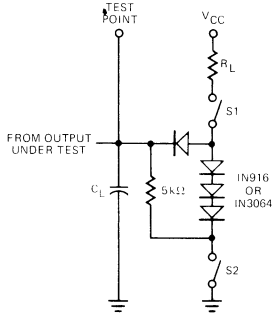
Am54S/74S242

Am54S/74S243

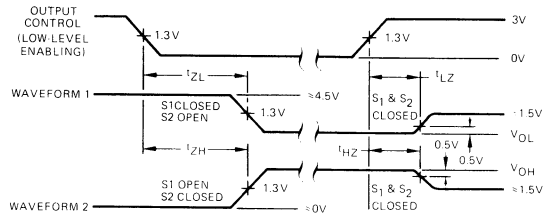
Am54S/74S244

Parameter	Description	Test Conditions	Am54S/74S240			Am54S/74S241			Units
			Min.	Typ.	Max.	Min.	Typ.	Max.	
t_{PLH}	Propagation Delay Time, Low-to-High-Level Output	$C_L = 50\text{pF}, R_L = 90\Omega$ (Note 3)		4.5	7.0		6.0	9.0	ns
t_{PHL}	Propagation Delay Time, High-to-Low-Level Output			4.5	7.0		6.0	9.0	ns
t_{ZL}	Output Enable Time to Low Level			10	15		10	15	ns
t_{ZH}	Output Enable Time to High Level			6.5	10		8.0	12	ns
t_{LZ}	Output Disable Time from Low Level	$C_L = 5.0\text{pF}, R_L = 90\Omega$ (Note 3)		10	15		10	15	ns
t_{HZ}	Output Disable Time from High Level			6.0	9.0		6.0	9.0	ns

LOAD CIRCUIT FOR THREE-STATE OUTPUTS



VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES, THREE-STATE OUTPUTS



- Notes: 1. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
- 2. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- 3. In the examples above, the phase relationships between inputs and outputs have been chosen arbitrarily. PRR \leq 1.0MHz, $Z_{OUT} \approx 50\Omega$ and $t_r \leq 2.5ns$, $t_f \leq 2.5ns$.

FUNCTION TABLES

Am54S/74S242

INPUTS		OUTPUTS	
$\overline{1G}$	2G	A	Y
H	L	X	Z
L	H	L	H
L	H	H	L

Am54S/74S240

INPUTS	OUTPUT	
\overline{G}	A	Y
H	X	Z
L	H	L
L	L	H

Am54S/74S241
Am54S/74S243

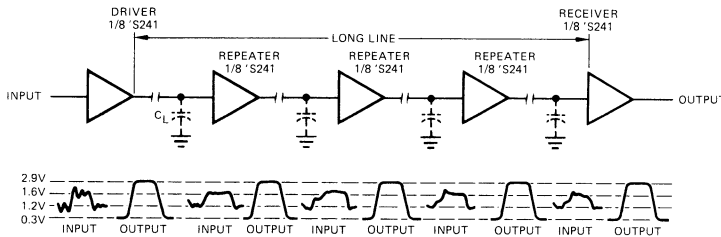
INPUTS			OUTPUTS	
$\overline{1G}$	2G	A	Y	Z
H	L	X	Z	Z
L	H	H	H	H
L	H	L	L	L

Am54S/74S244

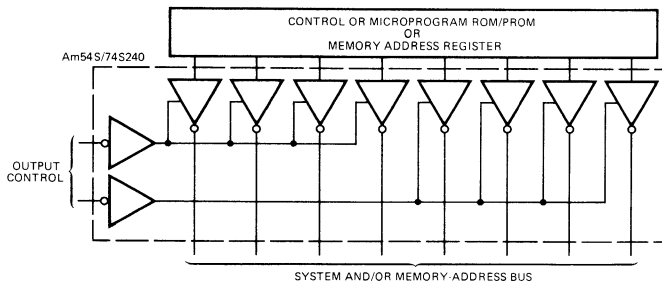
INPUTS	OUTPUT	
\overline{G}	A	Z
H	X	Z
L	H	H
L	L	L

APPLICATIONS

Am54S/74S241'S USED AS REPEATER/LEVEL RESTORER

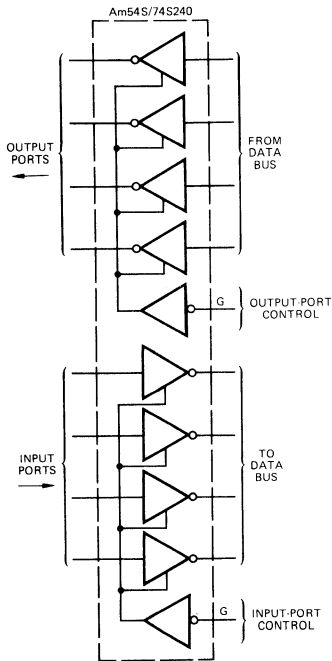


'S240 USED AS SYSTEM AND/OR MEMORY BUS DRIVER – 4-BIT ORGANIZATION CAN BE APPLIED TO HANDLE BINARY OR BCD

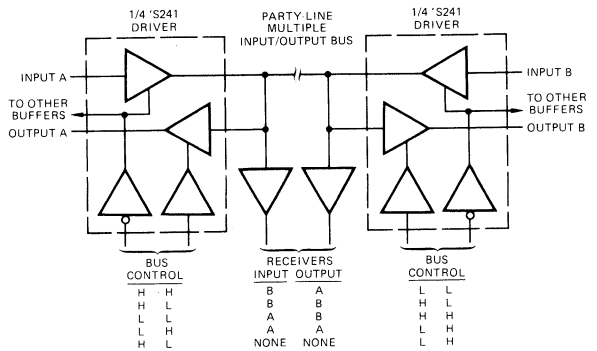


APPLICATIONS (Cont.)

INDEPENDENT 4-BIT BUS DRIVERS/RECEIVERS IN A SINGLE PACKAGE

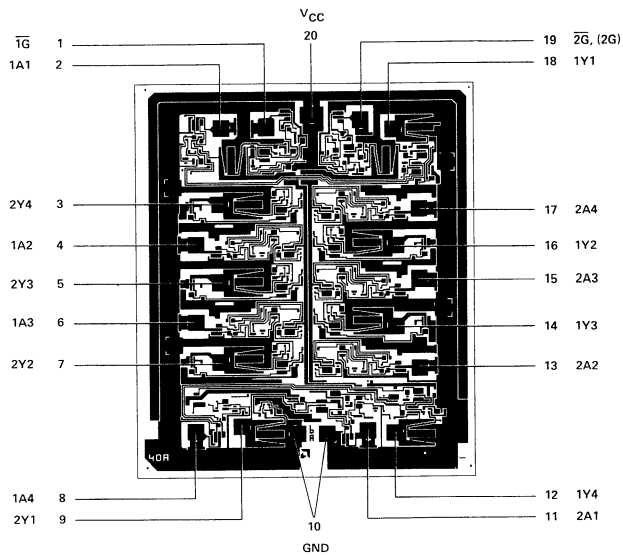


PARTY-LINE BUS SYSTEM WITH MULTIPLE INPUTS, OUTPUTS, AND RECEIVERS



Metallization and Pad Layout

Am54S/74S240 • Am54S/74S241 • Am54S/74S244



DIE SIZE 0.093" X 0.109"

Am54S/74S257 • Am54S/74S258

Quadruple 2-Line To 1-Line Data

Distinctive Characteristics

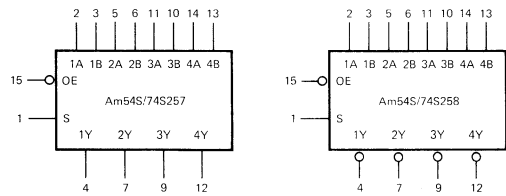
- Three-state outputs interface directly with bus organized systems
- Schottky clamp provides improved AC performance
- Pin assignments identical with Am54S/74S157 and Am54S/74S158
- 100% reliability assurance testing in compliance with MIL-STD-883

FUNCTIONAL DESCRIPTION

The 2-line to 1-line data selector multiplexer can be used to transfer data to a common data bus directly by using the three-state capability of the device. With the output control (\overline{OE}) HIGH, the four outputs of the data selector are in the high impedance state. With the output control LOW, the selected four bits (A or B inputs) are bussed onto the four data lines.

The typical propagation delay times from data input to output average 4.8ns for the Am54S/74S257 and 4ns for the Am54S/74S258. Also, to minimize the possibility that two outputs will attempt to drive the common bus to opposite logic levels, the output enable circuitry is designed such that the output disable times are shorter than the output enable times.

LOGIC SYMBOL

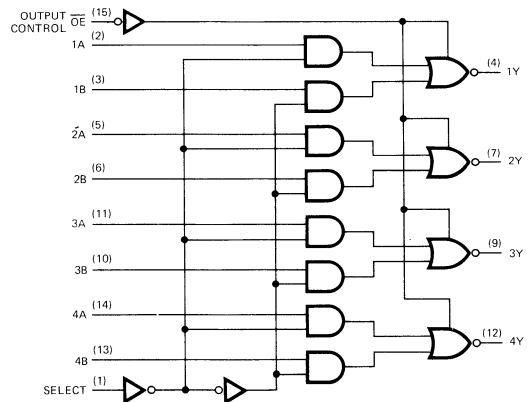
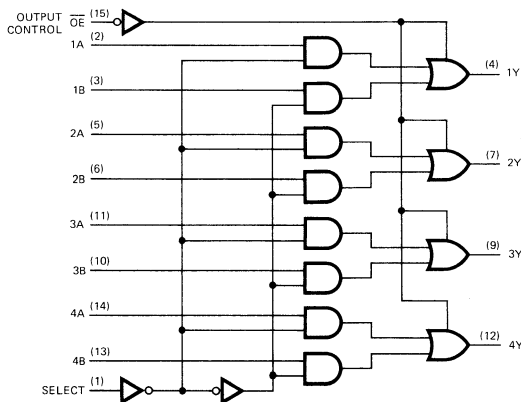


V_{CC} = Pin 16
GND = Pin 8

Am54S257, Am74S257

LOGIC DIAGRAMS

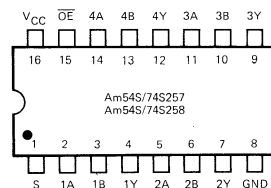
Am54S258, Am74S258



ORDERING INFORMATION

Package Type	Temperature Range	Am54S/74S257 Order Number	Am54S/74S258 Order Number
Molded DIP	0°C to +70°C	SN74S257N	SN74S258N
Hermetic DIP	0°C to +70°C	SN74S257J	SN74S258J
Dice	0°C to +70°C	SN74S257X	SN74S258X
Hermetic DIP	-55°C to +125°C	SN54S257J	SN54S258J
Hermetic Flat Pack	-55°C to +125°C	SN54S257W	SN54S258W
Dice	-55°C to +125°C	SN54S257X	SN54S258X

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation on flat package only.

Am54S/74S257/258

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5 V to +7 V
DC Voltage Applied to Outputs for High Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +5.5 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am74S257/S258	T _A = 0°C to +70°C	V _{CC} = 5.0 V ±5% (Com'l)	Min = 4.75 V	Max = 5.25 V
Am54S257/S258	T _A = -55°C to +125°C	V _{CC} = 5.0 V ±10% (Mil)	Min = 4.5 V	Max = 5.5 V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., V _{IN} = V _{IH} or V _{IL} , I _{OH} = -2mA	2.4	3.4		Volts	
		74S, I _{OH} = -6.5mA	2.4	3.2			
V _{OL}	Output LOW Voltage	V _{CC} = MIN., V _{IH} = 2V, V _{IL} = 0.8 V, I _{OL} = 20mA			0.5	Volts	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2			Volts	
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts	
I _{IL}	Unit Load Input LOW Current	S Input			-4	mA	
		Any Other			-2		
I _{IH} (Note 3)	Unit Load Input HIGH Current	S Input			100	μA	
		Any Other			50		
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1	mA	
I _O	Off-State (HIGH Impedance) Output Current	V _{CC} = MAX., V _O = 2.4V			50	μA	
		V _{CC} = MAX., V _O = 0.5V			-50		
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 0.0 V	-40		-100	mA	
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)	All Outputs HIGH	Am54S/74S257	44	68	mA
			Am54S/74S258	36	56		
			All Outputs LOW	Am54S/74S257	60	93	mA
			Am54S/74S258	52	81		
			All Outputs OFF	Am54S/74S257	64	99	mA
Am54S/74S258	56	87					

- Notes: 1. For conditions shown as MIN. or MAX. use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0 V, 25°C ambient and maximum loading.
 3. Actual Input Currents = Unit Load Current x Input Load Factor (See Loading Rules).
 4. Not more than one output should be shorted at a time and duration of the short circuit test should not exceed one second.
 5. I_{CC} is measured with all outputs open and all possible inputs grounded while achieving the stated output conditions.

Switching Characteristics (T_A = 25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units	
t _{PLH}	Data to Output	V _{CC} = 5 V, R _L = 280 Ω, C _L = 15 pF	S257	5	7.5	ns	
			S258	4	6		
t _{PHL}	Data to Output		S257	4.5	6.5	ns	
			S258	4	6		
t _{PLH}	Select to Output		S257	8.5	15	ns	
			S258	8	12		
t _{PHL}	Select to Output		S257	8.5	15	ns	
			S258	7.5	12		
t _{ZH}	Control to Output		V _{CC} = 5 V, R _L = 280 Ω, C _L = 5 pF		13	19.5	ns
t _{ZL}					14	21	
t _{HZ}	Control to Output			5.5	8.5	ns	
				9	14		
t _{LZ}							

FUNCTION TABLE

INPUTS				OUTPUTS	
Output Control	Select	A	B	Am54S/74S257	Am54S/74S258
H	X	X	X	Z	Z
L	L	L	X	L	H
L	L	H	X	H	L
L	H	X	L	L	H
L	H	X	H	H	L

H = HIGH
L = LOW

X = Don't Care
Z = High Impedance

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
			54S	74S
S	1	2	-	-
1A	2	1	-	-
1B	3	1	-	-
1Y	4	-	40	130
2A	5	1	-	-
2B	6	1	-	-
2Y	7	-	40	130
GND	8	-	-	-
3Y	9	-	40	130
3B	10	1	-	-
3A	11	1	-	-
4Y	12	-	40	130
4B	13	1	-	-
4A	14	1	-	-
OE	15	1	-	-
VCC	16	-	-	-

A Schottky TTL Unit Load is defined as 50 μA measured at 2.7 V HIGH and -2.0mA measured at 0.5 V LOW.

FUNCTIONAL TERMS

1A, 2A, 3A, 4A The data inputs for the 4-bits of the A word.

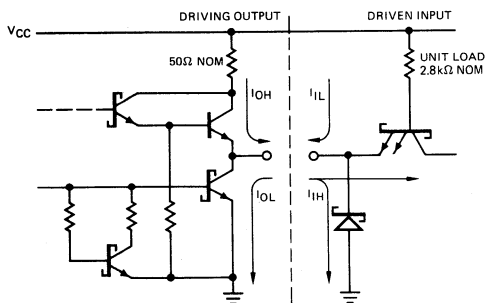
1B, 2B, 3B, 4B The data inputs for the 4-bits of the B word.

1Y, 2Y, 3Y, 4Y The four outputs of the multiplexer.

OE Output Control When the output control is HIGH, the four outputs are in the high impedance state. When the output control is LOW, the selected A or B input is present at the output.

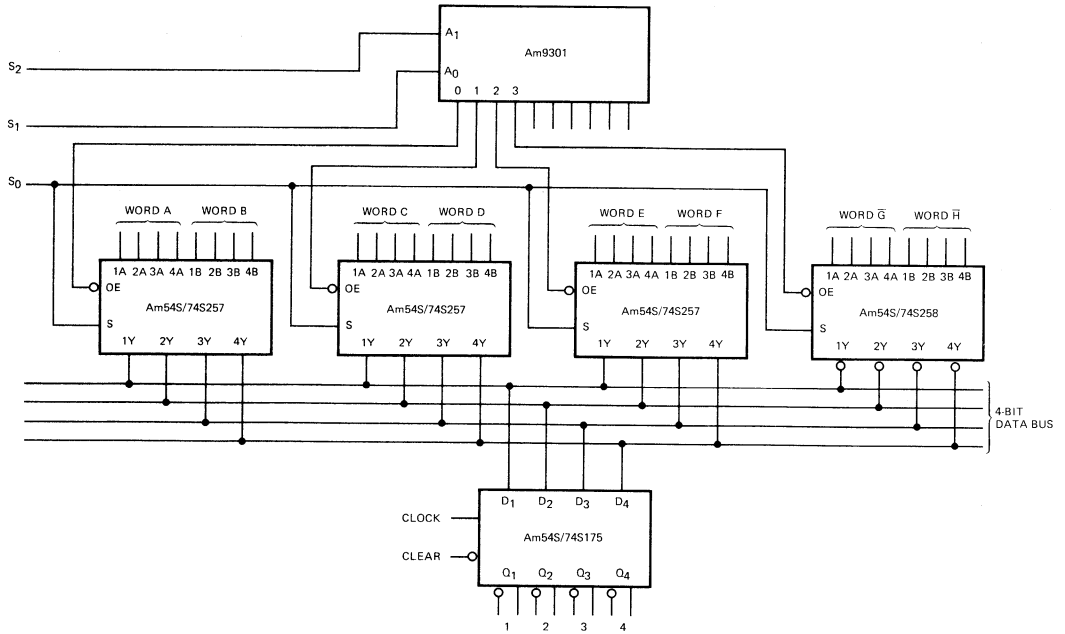
S Select When the select input is LOW, the A word is present at the output. When the select input is HIGH, the B word is present at the output.

SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown

APPLICATIONS



8-Word, 4-Bit Multiplexer

APPLICATION BRIEF – THREE STATE OUTPUTS

When a three-state Schottky output is in the high-impedance state, the maximum off-state leakage current is specified as $50\mu\text{A}$ at 2.4V and $-50\mu\text{A}$ at 0.5V. This leakage loading must be added to the input loading of the devices connected to the data bus for worst-case design. For this reason, the output HIGH source current of the three-state devices are specified with $I_{OH} = -2\text{mA}$ for the Am54S series and $I_{OH} = -6.5\text{mA}$ for the Am74S series. The output LOW sink current for all Am54S/74S devices is specified as $I_{OL} = 20\text{mA}$ at 0.5V.

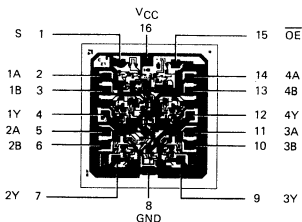
The high current sinking and sourcing capability allows many three-state outputs to be bus-organized and drive several TTL inputs reliably. An example of the I_{OH} and I_{OL} loading calculations is shown in Table I. The important factor for bus-organized three-state outputs is not to exceed either the HIGH-state or the LOW-state maximum loading.

TABLE I

NO. OF LOADING DEVICES ON BUS	TYPE LOAD	DATA BUS HIGH LOAD	DATA BUS LOW LOAD
36	54S/74S outputs Hi-Z	$50\mu\text{A} \times 36 = 1.8\text{mA}$	$-50\mu\text{A} \times 36 = -1.8\text{mA}$
4	54S/74S inputs	$50\mu\text{A} \times 4 = .2\text{mA}$	$-2\text{mA} \times 4 = -8.0\text{mA}$
		2.0mA	-9.8mA
OUTPUT LOADING USED	Am54S	MAXIMUM	~ 50%
	Am74S	~ 31%	~ 50%

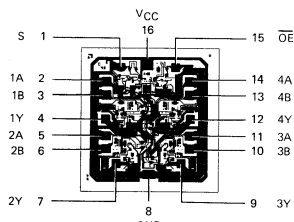
Metallization and Pad Layouts

Am54S/74S257



DIE SIZE 0.065" X 0.069"

Am54S/74S258



DIE SIZE 0.065" X 0.069"

Am54S/74S350

Four-Bit Shifter With Three-State Outputs

Distinctive Characteristics

- Shifts 4-bits of data to 0, 1, 2 or 3 places under control of two select lines.
- Three-state outputs for bus organized systems.

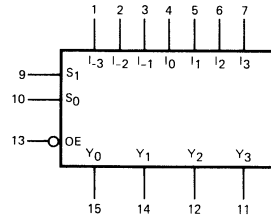
- 6.5ns typical data propagation delay.
- 100% reliability assurance testing in compliance with MIL-STD-883.

FUNCTIONAL DESCRIPTION

The Am54S/74S350 is a combinatorial logic circuit that accepts a four-bit data word and shifts the word 0, 1, 2 or 3 places. The number of places to be shifted is determined by a two-bit select field S_0 and S_1 . An active-LOW enable controls the three-state outputs. This feature allows expansion of shifting over a larger number of places with one delay.

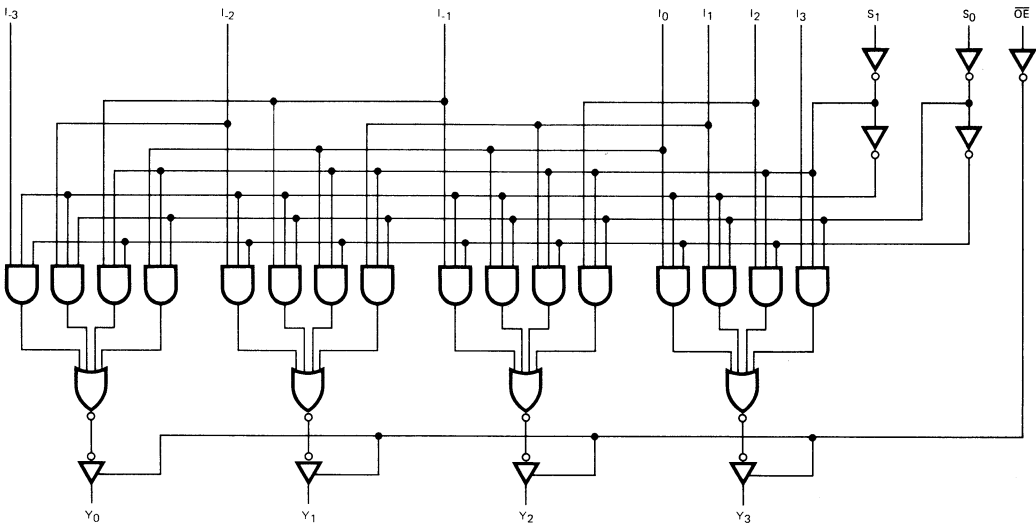
By suitable interconnection, the Am54S/74S350 can be used to shift any number of bits any number of places up or down. Shifting can be logical, with logic zeroes pulled in at either or both ends of the shifting field; arithmetic, where the sign bit is repeated during a shift down; or end around, where the data word forms a continuous loop.

LOGIC SYMBOL

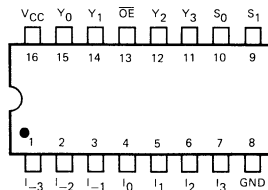


V_{CC} = Pin 16
GND = Pin 8

LOGIC DIAGRAM



CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 V to +7 V
DC Voltage Applied to Outputs for High Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +5.5 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

SN74S350	T _A = 0°C to +70°C	V _{CC} = 5.0V ± 5% (COM'L)	MIN. = 4.75 V	MAX. = 5.25 V
SN54S350	T _A = -55°C to +125°C	V _{CC} = 5.0V ± 10% (MIL)	MIN. = 4.5 V	MAX. = 5.5 V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ.(Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., MIL, I _{OH} = -2mA V _{IN} = V _{IH} or V _{IL} COM'L, I _{OH} = -6.5mA	2.4	3.4		Volts
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{IL}	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5 V			-2.0	mA
I _{IH}	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7 V			50	μA
I _O	Off State (High Impedance) Output Current	V _{CC} = MAX., V _O = 2.4 V V _O = 0.5 V			50 -50	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5 V			1.0	mA
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX., V _{OUT} = 0.0 V	-40		-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX., All outputs open, All inputs = GND		60	85	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	Data Input to Output	V _{CC} = 5.0V, C _L = 15pF, R _L = 280Ω		5	7.5	ns
t _{PHL}				8	12	
t _{PLH}	Select to Output			11	17	ns
t _{PHL}				13	20	
t _{ZH}	Output Control \overline{OE} to Output				19.5	ns
t _{ZL}					21	
t _{HZ}	Output Control \overline{OE} to Output	V _{CC} = 5V, C _L = 5pF, R _L = 280Ω		5	8	ns
t _{LZ}				10	15	

Am54S/74S373 • Am54S/74S533

Octal Latches with Three-State Outputs

DISTINCTIVE CHARACTERISTICS

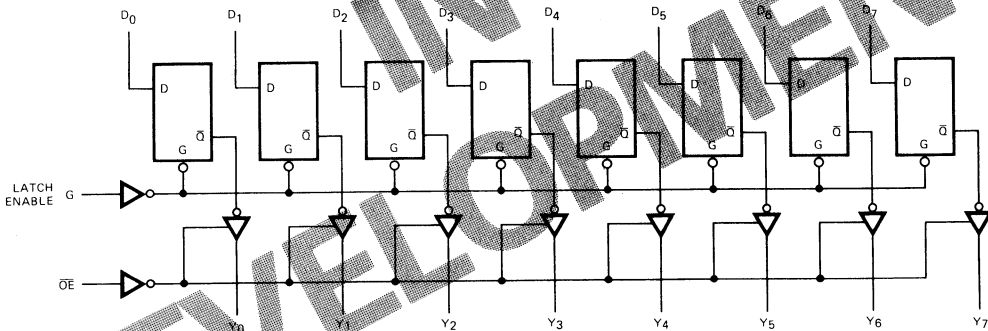
- 8 latches in a single package
- Am54S/74S373 has non-inverting outputs
- Am54S/74S533 has inverting outputs
- $V_{OL} = 0.5V$ (max) at $I_{OL} = 20mA$
- Three-state outputs interface directly with bus organized systems
- Hysteresis on latch enable input for improved noise margin
- High speed – Clock to output 12ns typical
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am54S/74S373 is an octal latch with three-state outputs for bus organized system applications. The latching flip-flops appear to be transparent to the data (data changes asynchronously) when latch enable, G, is HIGH. When G is LOW, the data that meets the set-up times is latched. Data appears on the bus when the output enable, \overline{OE} , is LOW. When \overline{OE} is HIGH the bus output is in the high-impedance state.

Am25S373 and Am25S533 versions are also available offering $V_{OL} = 0.5V$ (max) at $I_{OL} = 32mA$.

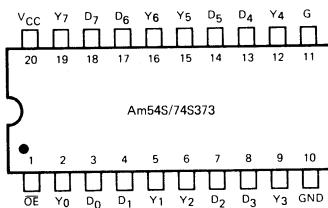
LOGIC DIAGRAM
Am54S/74S373



Outputs Y_0 through Y_7 are inverted on the Am54S/74S533.

MPR-360

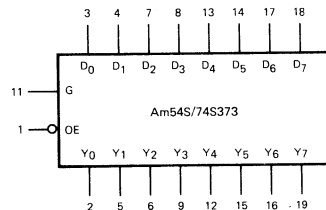
CONNECTION DIAGRAM
Top View



Note: Pin 1 is marked for orientation.

MPR-361

LOGIC SYMBOL



V_{CC} = Pin 20
GND = Pin 10

MPR-362

Am54S/74S374 • Am54S/74S534

8-Bit Registers with Three-State Outputs

DISTINCTIVE CHARACTERISTICS

- Eight-bit, high speed parallel registers
- Am54S/74S374 has non-inverting outputs
- Am54S/74S534 has inverting outputs
- Positive, edge-triggered, D-type flip-flops
- Buffered common clock and buffered common three-state control
- $V_{OL} = 0.5V$ (max) at $I_{OL} = 20mA$
- High speed – Clock to output 11ns typical
- 100% product assurance screening to MIL-STD-883 requirements

FUNCTIONAL DESCRIPTION

The Am54/74S374 and Am54S/74S534 are eight-bit registers built using high speed Schottky technology. The registers consist of eight D-type flip-flops with a buffered common clock and a buffered three-state output control. When the output enable (\overline{OE}) input is LOW, the eight outputs are enabled. When the \overline{OE} input is HIGH, the outputs are in the three-state condition.

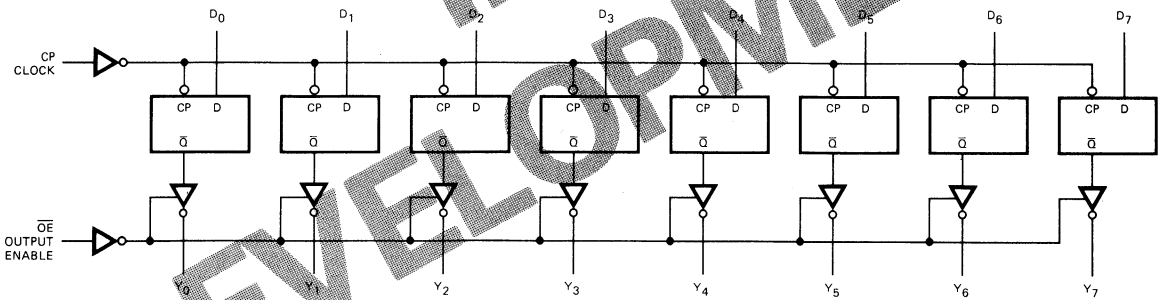
Input data meeting the set-up and hold time requirements of the D inputs is transferred to the Y outputs on the LOW-to-HIGH transition of the clock input.

The devices are packaged in a space-saving (0.3-inch row spacing) 20-pin package.

Am25S374 and Am25S534 versions are also available offering $V_{OL} = 0.5V$ (max) at $I_{OL} = 32mA$.

LOGIC DIAGRAM

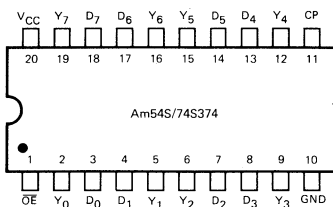
Am54S/74S374



Outputs Y_0 through Y_7 are inverted on the Am54/74S534.

MPR-363

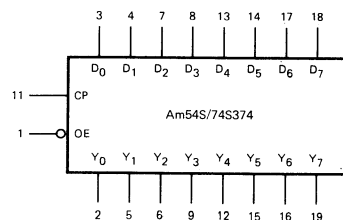
CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

MPR-364

LOGIC SYMBOL



V_{CC} = Pin 20
GND = Pin 10

MPR-365

Am54S/74S378 • Am54S/74S379

Hex/Quad Parallel D Registers With Register Enable

Distinctive Characteristics

- 4-bit and 6-bit high-speed parallel registers
- Common clock and common enable

- Positive edge triggered D flip-flops
- 100% reliability assurance testing in compliance with MIL-STD-883.

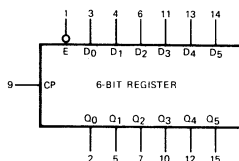
FUNCTIONAL DESCRIPTION

The Am54S/74S378 is a 6-bit, high-speed Schottky register with a buffered common register enable. The Am54S/74S379 is a 4-bit register with a buffered common register enable. The devices are similar to the Am54S/74S174 and Am54S/74S175 but feature the common register enable rather than common clear.

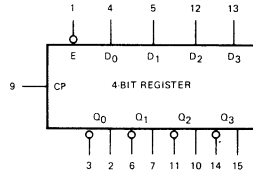
Both registers will find application in digital systems where information is associated with a logic gating signal. When the enable is LOW, data on the D inputs is stored in the register on the positive going edge of the clock pulse. When the enable is HIGH, the register will not change state regardless of the clock or data input transitions.

LOGIC SYMBOLS

Am54S/74S378



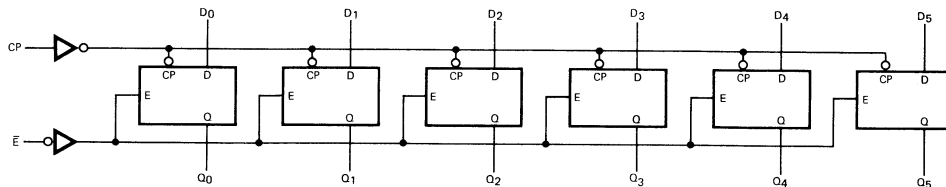
Am54S/74S379



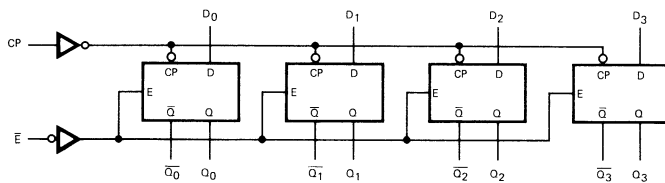
V_{CC} = Pin 16
GND = Pin 8

LOGIC DIAGRAMS

Am54S/74S378



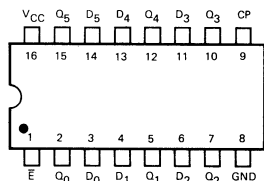
Am54S/74S379



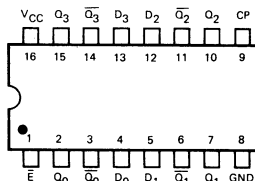
CONNECTION DIAGRAMS

Top Views

Am54S/74S378



Am54S/74S379



Note: Pin 1 is marked for orientation.

4

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

SN74S378, SN74S379 T_A = 0°C to +70°C V_{CC} = 5.0V ±5% (COM'L) MIN. = 4.75V MAX. = 5.25V
 SN54S378, SN54S379 T_A = -55°C to +125°C V_{CC} = 5.0V ±10% (MIL) MIN. = 4.5V MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1mA V _{IN} = V _{IH} or V _{IL}	COM'L	2.7	3.4		Volts
			MIL	2.5	3.4		
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts	
I _{IL}	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V			-2	mA	
I _{IH}	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			50	μA	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA	
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.	-40		-100	mA	
I _{CC}	Power Supply Current (Note 4)	V _{CC} = MAX.	S378		90	144	mA
			S379		60	96	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Outputs open; enable grounded; data inputs at 4.5V, measured after a momentary ground, then 4.5V applied to the clock input.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	Clock to Output	V _{CC} = 5.0V, C _L = 15 pF, R _L = 280Ω	4	8	12	ns
t _{PHL}	Clock to Output		4	11.5	17	ns
t _{pw}	Clock Pulse Width		7			ns
t _s	Data		5.5			ns
t _s	Enable		9			ns
t _h	Data		3			ns
t _h	Enable		3			ns

Am54S/74S388

Quad D Register With Standard And Three-State Outputs

Distinctive Characteristics

- Advanced Schottky technology
- Four D-type flip-flops
- Four standard totem-pole outputs
- Four three-state outputs
- 75 MHz clock frequency
- 100% reliability assurance testing in compliance with MIL-STD-883

FUNCTIONAL DESCRIPTION

The Am54S/74S388 consists of four D-type flip-flops with a buffered common clock. Information meeting the set-up and hold requirements on the D inputs is transferred to the Q outputs on the LOW-to-HIGH transition of the clock.

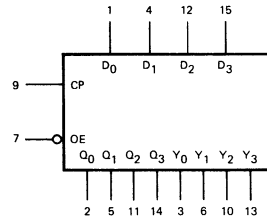
The same data as on the Q outputs is enabled at the three-state Y outputs when the "output control" (OE) input is LOW. When the OE input is HIGH, the Y outputs are in the high-impedance state.

The Am54S/74S388 is a 4-bit, high-speed Schottky register intended for use in real-time signal processing systems where the standard outputs are used in a recursive algorithm and the three state outputs provide access to a data bus to dump the results after a number of iterations.

The device can also be used as an address register or status register in computers or computer peripherals.

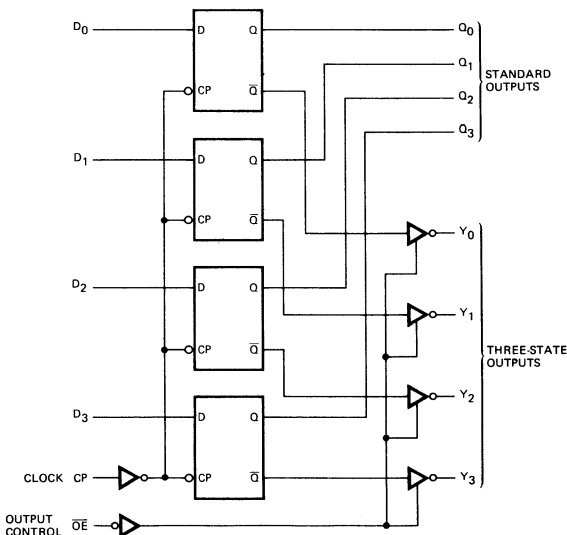
Likewise, the Am54S/74S388 is also useful in certain display applications where the standard outputs can be decoded to drive LED's (or equivalent) and the three-state outputs are bus organized for occasional interrogation of the data as displayed.

LOGIC SYMBOL

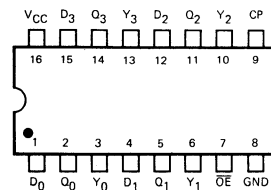


V_{CC} = Pin 16
GND = Pin 8

LOGIC DIAGRAM



CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

Am54S/74S388

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

SN74S388	T _A = 0°C to +70°C	V _{CC} = 5.0V ± 5% (COM'L)	MIN. = 4.75V	MAX. = 5.25V
SN54S388	T _A = -55°C to +125°C	V _{CC} = 5.0V ± 10% (MIL)	MIN. = 4.5V	MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units	
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., V _{IN} = V _{IH} or V _{IL}	Q I _{OH} = -1mA	MIL	2.5	3.4	Volts
				COM'L	2.7	3.4	
		Y	MIL, I _{OH} = -2mA		2.4	3.4	
			COM'L, I _{OH} = -6.5mA		2.4	3.2	
V _{OL}	Output LOW Voltage (Note 6)	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts	
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts	
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts	
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts	
I _{IL}	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V			-2.0	mA	
I _{IH}	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			50	μA	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA	
I _O	Y Output Off-State Leakage Current	V _{CC} = MAX.	V _O = 2.4V		50	μA	
			V _O = 0.4V		-50		
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.	-40		-100	mA	
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 4)		80	130	mA	

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, T_A = 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. I_{CC} is measured with all inputs at 4.5V and all outputs open.
 5. Measured on Q outputs with Y outputs open. Measured on Y outputs with Q outputs open.

Switching Characteristics (T_A = +25°C, V_{CC} = 5.0V, R_L = 280Ω)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units	
t _{PLH}	Clock to Q Output	C _L = 15pF		6.0	9.0	ns	
t _{PHL}				8.5	13		
t _{pw}	Clock Pulse Width		HIGH	7.0		ns	
			LOW	9.0			
t _s	Data		5.0		ns		
t _h	Data		3.0		ns		
t _{PLH}	Clock to Y Output (OE LOW)				6.0	9.0	ns
t _{PHL}					8.5	13	
t _{ZH}	Output Control to Output		C _L = 15pF		12.5	19	ns
t _{ZL}					12	18	
t _{HZ}		4.0			6.0		
t _{LZ}		7.0			10.5		
f _{max}	Maximum Clock Frequency	C _L = 15pF	75	100		MHz	

Am54S/74S399

Quad Two-Input, High-Speed Register

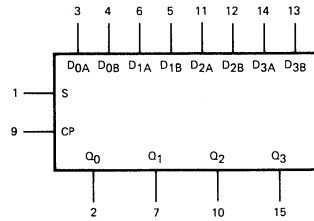
Distinctive Characteristics

- Four-bit register accepts data from one of two 4-bit input fields
- Edge triggered clock action
- High-speed Schottky technology
- 100% reliability assurance testing in compliance with MIL-STD-883

FUNCTIONAL DESCRIPTION

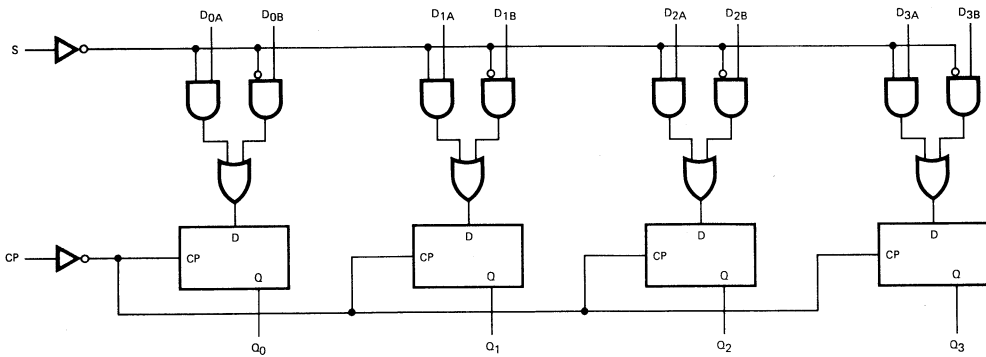
The Am54S/74S399 is a dual port high-speed, four-bit register using advanced Schottky technology to reduce the effect of transistor storage time. The register consists of four D flip-flops with a buffered common clock, and a two-input multiplexer at the input of each flip-flop. A common select line, S, controls the four multiplexers. Data on the four inputs selected by the S line is stored in the four flip-flops at the clock LOW-to-HIGH transition. When the S input is LOW, the D_{1A} input data will be stored in the register. When the S input is HIGH, the D_{1B} input data will be stored in the register.

LOGIC SYMBOL

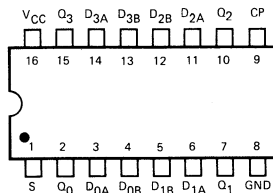


V_{CC} = Pin 16
GND = Pin 8

LOGIC DIAGRAM



CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

4

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 V to +7 V
DC Voltage Applied to Outputs for High Output State	-0.5 V to +V _{CC} max.
DC Input Voltage	-0.5 V to +5.5 V
DC Output Current, Into Outputs	30 mA
DC Input Current	-30 mA to +5.0 mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

SN74S399	T _A = 0°C to +70°C	V _{CC} = 5.0 V ± 5% (COM'L)	MIN. = 4.75 V	MAX. = 5.25 V
SN54S399	T _A = -55°C to +125°C	V _{CC} = 5.0 V ± 10% (MIL)	MIN. = 4.5 V	MAX. = 5.5 V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1.0mA	COM'L	2.7	3.4	Volts
		V _{IN} = V _{IH} or V _{IL}	MIL	2.5	3.4	
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20.0mA V _{IN} = V _{IH} or V _{IL}		0.3	0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{IL}	Unit Load Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5 V			-2.0	mA
I _{IH}	Unit Load Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7 V			50	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5 V			1.0	mA
I _{SC}	Output Short Circuit Current (Note 3)	V _{CC} = MAX.	-40		-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 4)		75	120	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0 V, 25°C ambient and maximum loading.
 3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 4. Measured with Select and Clock inputs at 4.5V; all data inputs at 0V; all outputs open.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	Clock to Q HIGH	V _{CC} = 5.0 V, C _L = 15 pF, R _L = 280 Ω		8	12	ns
t _{PHL}	Clock to Q LOW			11.5	17	ns
t _{pw}	Clock Pulse Width		7			ns
t _s	Data Set-up Time		5.5			ns
t _s	Select Input Set-up Time		10			ns
t _h	Data Hold Time		3			ns
t _h	Select Input Hold Time		3			ns

Am54S/74S412

Eight-Bit Input/Output Port

The 54S/74S412 is Texas Instruments' second source part number to the AMD/Intel 8212 device.

See the Am8212 data sheet for full information.

Am3212 • Am8212

Eight-Bit Input/Output Port

Distinctive Characteristics

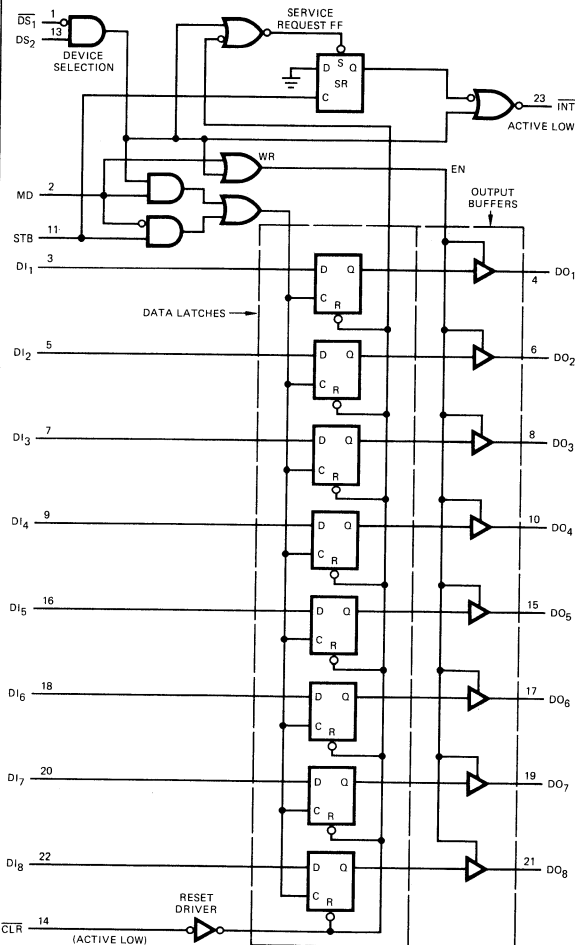
- Fully parallel, 8-bit data register and buffer replacing latches, multiplexers and buffers needed in micro-processor systems.
- 4.0V output high voltage for direct interface to MOS microprocessors, such as the Am9080A family.
- Input load current 250 μ A max.
- Reduces system package count

- Available for operation over both commercial and military temperature ranges.
- Advanced Schottky processing with 100% reliability assurance testing in compliance with MIL-STD-883.
- Service request flip-flop for interrupt generation
- Three-state outputs sink 15mA
- Asynchronous register clear with clock over-ride

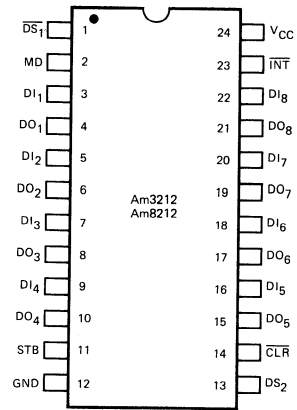
FUNCTIONAL DESCRIPTION

All of the principal peripheral and input/output functions of a Microcomputer System can be implemented with the Am3212 • Am8212. The Am3212 • Am8212 input/output port consists of an 8-latch with 3-state output buffers along with control and device selection logic, which can be used to implement latches, gated buffers or multiplexers.

LOGIC DIAGRAM



CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

PIN DEFINITION

DI ₁ – DI ₈	DATA IN
DO ₁ – DO ₈	DATA OUT
\overline{DS}_1 – \overline{DS}_2	DEVICE SELECT
MD	MODE
STB	STROBE
\overline{INT}	INTERRUPT (ACTIVE LOW)
\overline{CLR}	CLEAR (ACTIVE LOW)

ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Hermetic DIP	-55°C to +125°C	AM8212DM
Hermetic DIP	0°C to +70°C	D8212
Molded DIP	0°C to +70°C	P8212
Dice	0°C to +70°C	AM8212XC
Hermetic DIP	0°C to +70°C	D3212
Hermetic DIP	-55°C to +125°C	MD3212
Molded DIP	0°C to +70°C	P3212

FUNCTIONAL DESCRIPTION (Cont'd)**Data Latch**

The 8 flip-flops that make up the data latch are of a "D" type design. The output (Q) of the flip-flop will follow the data input (D) while the clock input (C) is high. Latching will occur when the clock (C) returns low.

The data latch is cleared by an asynchronous reset input (CLR). (Note: Clock (C) Overrides Reset (CLR)).

Output Buffer

The outputs of the data latch (Q) are connected to 3-state, non-inverting output buffers. These buffers have a common control line (EN); this control line either enables the buffer to transmit the data from the outputs of the data latch (Q) or disables the buffer, forcing the output into a high impedance state. (3-state). This high-impedance state allows the Am3212 • Am8212 to be connected directly onto the microprocessor bi-directional data bus.

Control Logic

The Am3212 • Am8212 has control inputs \overline{DS}_1 , DS_2 , MD And STB. These inputs are used to control device selection, data latching, output buffer state and service request flip-flop.

 \overline{DS}_1 , DS_2 (Device Select)

These 2 inputs are used for device selection. When \overline{DS}_1 is low and DS_2 is high ($\overline{DS}_1 \cdot DS_2$) the device is selected. In the selected state the output buffer is enabled and the service request flip-flop (SR) is asynchronously set.

MD (Mode)

This input is used to control the state of the output buffer and to determine the source of the clock input (C) to the data latch.

When MD is high (output mode) the output buffers are enabled and the source of clock (C) to the data latch is from the device selection logic ($\overline{DS}_1 \cdot DS_2$).

When MD is low (input mode) the output buffer state is determined by the device selection logic ($\overline{DS}_1 \cdot DS_2$) and the source of clock (C) to the data latch is the STB (Strobe) input.

STB (Strobe)

This input is used as the clock (C) to the data latch for the input mode MD = 0) and to synchronously reset the service request flip-flop (SR).

Note that the SR flip-flop is negative edge triggered.



Service Request Flip-Flop

The SR flip-flop is used to generate and control interrupts in microcomputer systems. It is asynchronously set by the CLR input (active low). When the (SR) flip-flop is set it is in the non-interrupting state.

The output of the (SR) flip-flop (Q) is connected to an inverting input of a "NOR" gate. The other input to the "NOR" gate is non-inverting and is connected to the device selection logic ($\overline{DS}_1 \cdot DS_2$). The output of the "NOR" gate (\overline{INT}) is active low (interrupting state) for connection to active low input priority generating circuits.

TRUTH TABLE

STB	MD	$\overline{DS}_1 - DS_2$	Data Out Equals
0	0	0	Three-State
1	0	0	Three-State
0	1	0	Data Latch
1	1	0	Data Latch
0	0	1	Data Latch
1	0	1	Data In
0	1	1	Data In
1	1	1	Data In

CLR	$\overline{DS}_1 - DS_2$	STB	SR*	\overline{INT}
0	0	0	1	1
0	1	0	1	0
1	1		0	0
1	1	0	1	0
1	0	0	1	1
1	1		1	0

\overline{CLR} — Resets Data Latch

— Sets SR Flip-Flop (no effect on Output Buffer)

* Internal SR Flip-Flop

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage	-0.5V to +7.0V
Output Voltage	-0.5V to +7.0V
Input Voltages	-1.0V to +5.5V
Output Current (Each Output)	125mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

P8212, D8212, P3212, D3212 (COM'L)	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 5\%$
Am8212DM, MD3212 (MIL)	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$	$V_{CC} = 5.0\text{V} \pm 10\%$

DC CHARACTERISTICS

Parameters	Description	Test Conditions	Min.	Typ. (Note 1)	Max.	Units	
I_F	Input Load Current ACK, DS ₂ , CR, DI ₁ - DI ₈ Inputs	$V_F = 0.45\text{V}$			-0.25	mA	
I_F	Input Load Current MD Input	$V_F = 0.45\text{V}$			-0.75	mA	
I_F	Input Load Current DS ₁ Input	$V_F = 0.45\text{V}$			-1.0	mA	
I_R	Input Leakage Current ACK, DS, CR, DI ₁ - DI ₈ Inputs	$V_R = 5.25\text{V}$			10	μA	
I_R	Input Leakage Current MO Input	$V_R = 5.25\text{V}$			30	μA	
I_R	Input Leakage Current DS ₁ Input	$V_R = 5.25\text{V}$			40	μA	
V_C	Input Forward Voltage Clamp	$I_C = -5.0\text{mA}$	COM'L		-1.0	Volts	
			MIL		-1.2		
V_{IL}	Input LOW Voltage		COM'L		0.85	Volts	
			MIL		0.80		
V_{IH}	Input HIGH Voltage		2.0			Volts	
V_{OL}	Output LOW Voltage	$I_{OL} = 15\text{mA}$			0.45	Volts	
V_{OH}	Output HIGH Voltage	$I_{OH} = -1.0\text{mA}$	COM'L	3.65	4.0	Volts	
			MIL		3.3		4.0
			MIL		3.5		4.0
I_{SC}	Short Circuit Output Current	$V_O = 0\text{V}$	-15		-75	mA	
$ I_{O} $	Output Leakage Current High Impedance	$V_O = 0.45\text{V}/5.25\text{V}$			20	μA	
I_{CC}	Power Supply Current	Note 2		90	130	mA	

AC CHARACTERISTICS (Note 3)

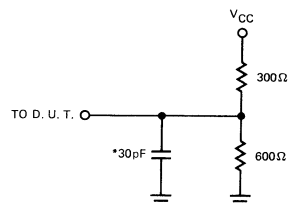
Parameters	Description	Min.	Typ. (Note 1)	Max.	Units
t_{pw}	Pulse Width	30	8		ns
t_{pd}	Data to Output Delay		12	30	ns
t_{we}	Write Enable to Output Delay		18	40	ns
t_{set}	Data Set-up Time	15			ns
t_h	Data Hold Time	20			ns
t_r	Reset to Output Delay		18	40	ns
t_s	Set to Output Delay		15	30	ns
t_e	Output Enable/Disable Time		14	45	ns
t_c	Clear to Output Delay		25	55	ns

CAPACITANCE (Note 4)

F = 1.0MHz, $V_{BIAS} = 2.5\text{V}$, $V_{CC} = +5.0\text{V}$, $T_A = 25^\circ\text{C}$

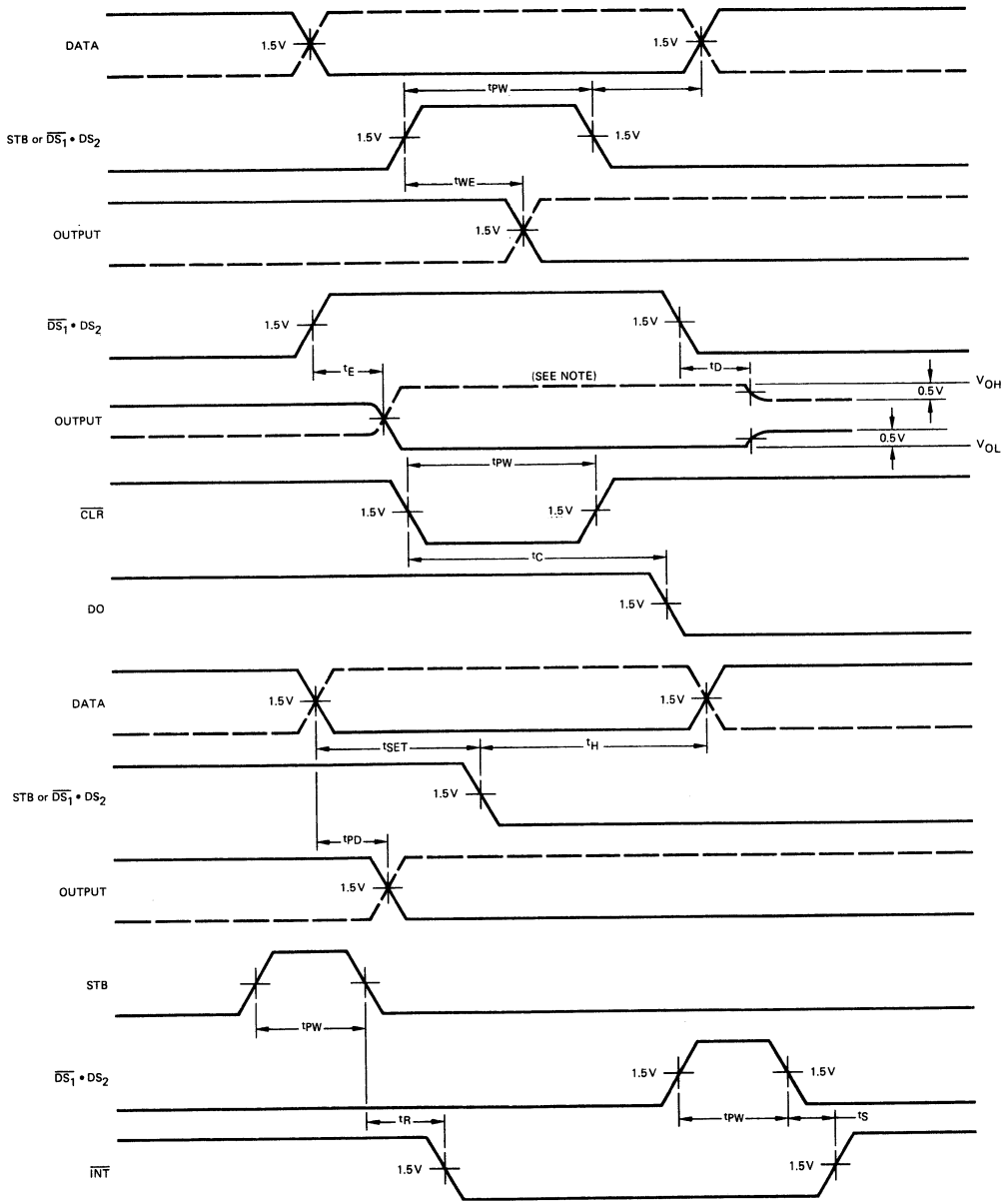
Parameters	Description	Typ.	Max.	Units
C_{IN}	DS ₁ MD Input Capacitance	9.0	12	pF
C_{IN}	DS ₂ , CK, ACK, DI ₁ - DI ₈ Input Capacitance	5.0	9.0	pF
C_{OUT}	DO ₁ - DO ₈ Output Capacitance	8.0	12	pF

- Notes: 1. Typical limits are at $V_{CC} = 5.0\text{V}$, 25°C ambient and maximum loading.
 2. CLR = STB = HIGH; DS₁ = DS₂ = MD = LOW; all data inputs are ground, all data outputs are open.
 3. Conditions of Test: a) Input pulse amplitude = 2.5V
 b) Input rise and fall times 5.0ns
 c) Between 1.0V and 2.0V measurements made at 1.5V with 15mA and 30pF Test Load.
 4. This parameter is sampled and not 100% tested.

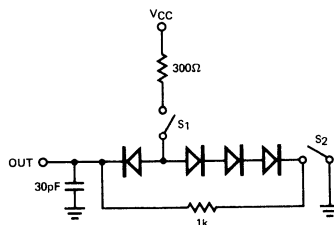
TEST LOAD (15mA and 30pF)

*Including Jig and Probe Capacitance.

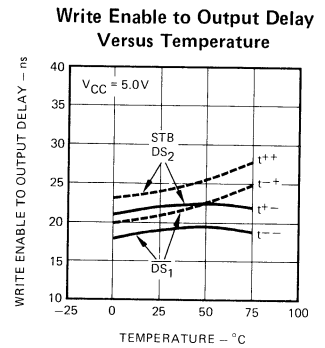
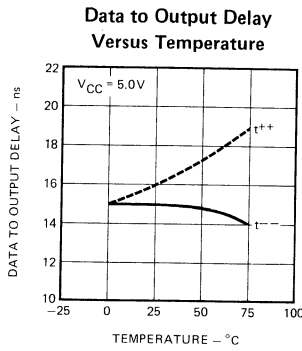
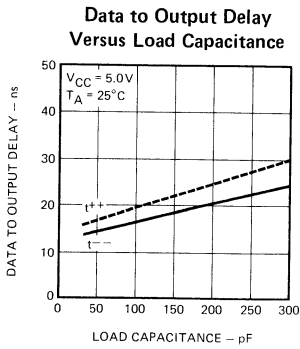
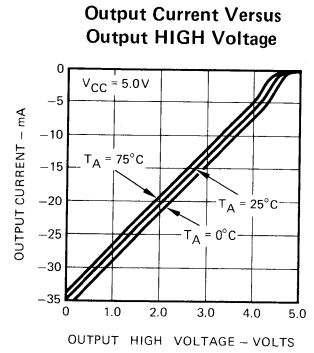
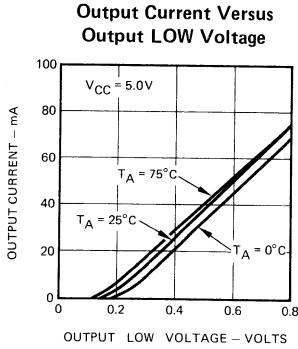
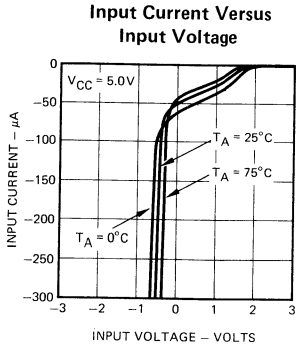
TIMING DIAGRAM



Note: Alternative Test Load.

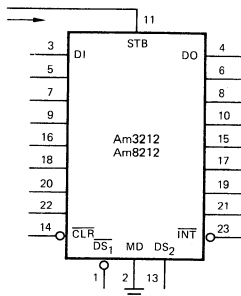


TYPICAL CHARACTERISTICS

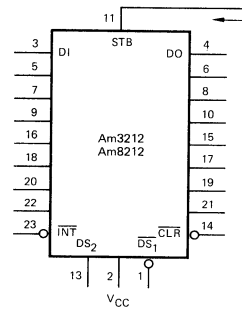


LOGIC SYMBOLS

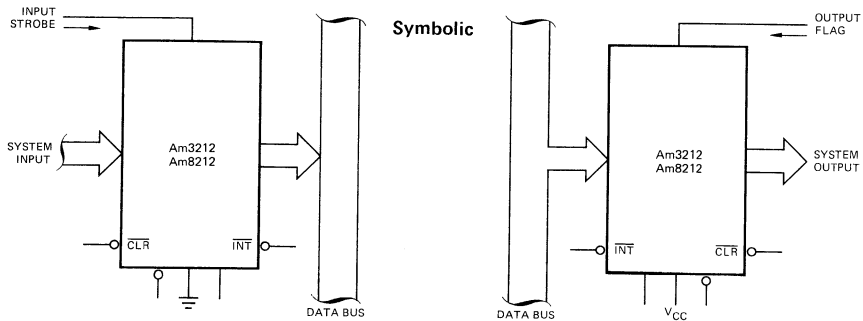
INPUT DEVICE



OUTPUT DEVICE



Detailed



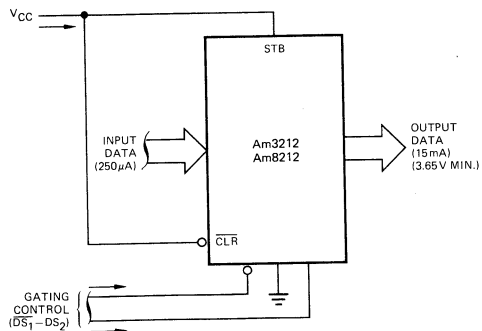
TYPICAL APPLICATIONS OF THE Am8212

GATED BUFFER (3-STATE)

By tying the mode signal low and the strobe input high, the data latch is acting as a straight through gate. The output buffers are then enabled from the device selection logic \overline{DS}_1 and DS_2 .

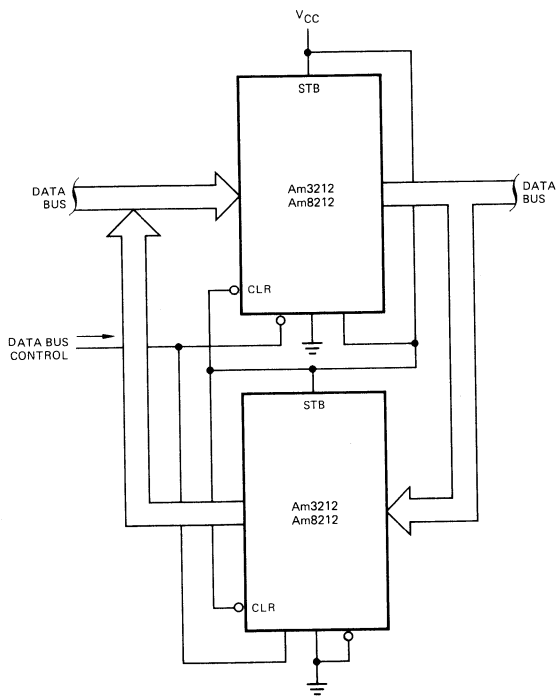
When the device selection logic is false, the outputs are 3-state.

When the device selection logic is true, the input data from the system is directly transferred to the output.



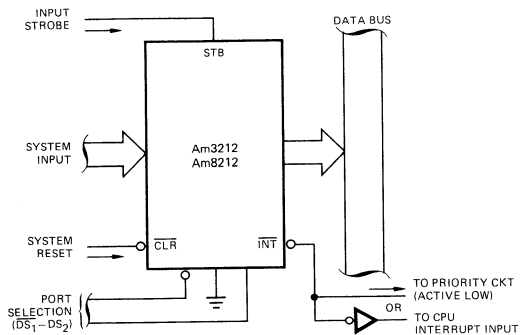
Bi-Directional Bus Driver

Two Am3212 • Am8212's wired back-to-back can be used as a symmetrical drive, bi-directional bus driver. The devices are controlled by the data bus input control which is connected to \overline{DS}_1 on the first Am3212 • Am8212 and to DS_2 on the second. While one device is active, and acting as a straight through buffer the other is in its 3-state mode.



Interrupting Input Port

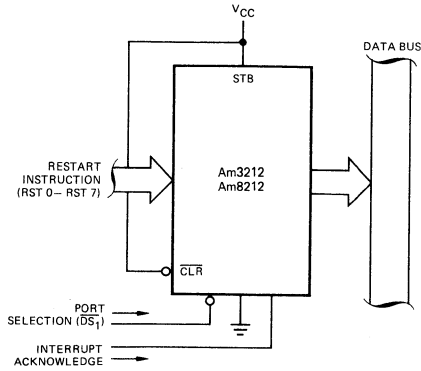
The Am3212 • Am8212 accepts a strobe from the system input source, which in turn clears the service request flip-flop and interrupts the processor. The processor then goes through a service routine, identifies the port, and causes the device selection logic to go true – enabling the system input data onto the data bus.



TYPICAL APPLICATIONS OF THE Am3212 (Cont'd)

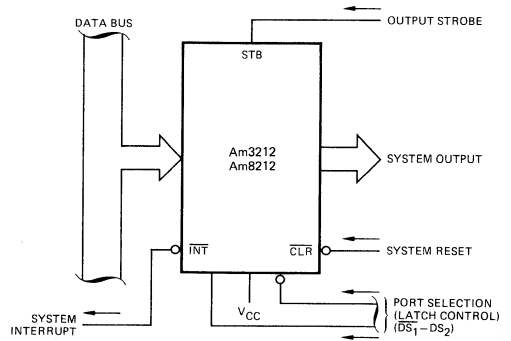
Interrupt Instruction Port

The Am3212 • Am8212 can be used to gate the interrupt instruction, normally RESTART instructions, onto the data bus. The device is enabled from the interrupt acknowledge signal from the microprocessor and from a port selection signal. This signal is normally tied to ground. (\overline{DS}_1 could be used to multiplex a variety of interrupt instruction ports onto a common bus).



Output Port (With Hand-Shaking)

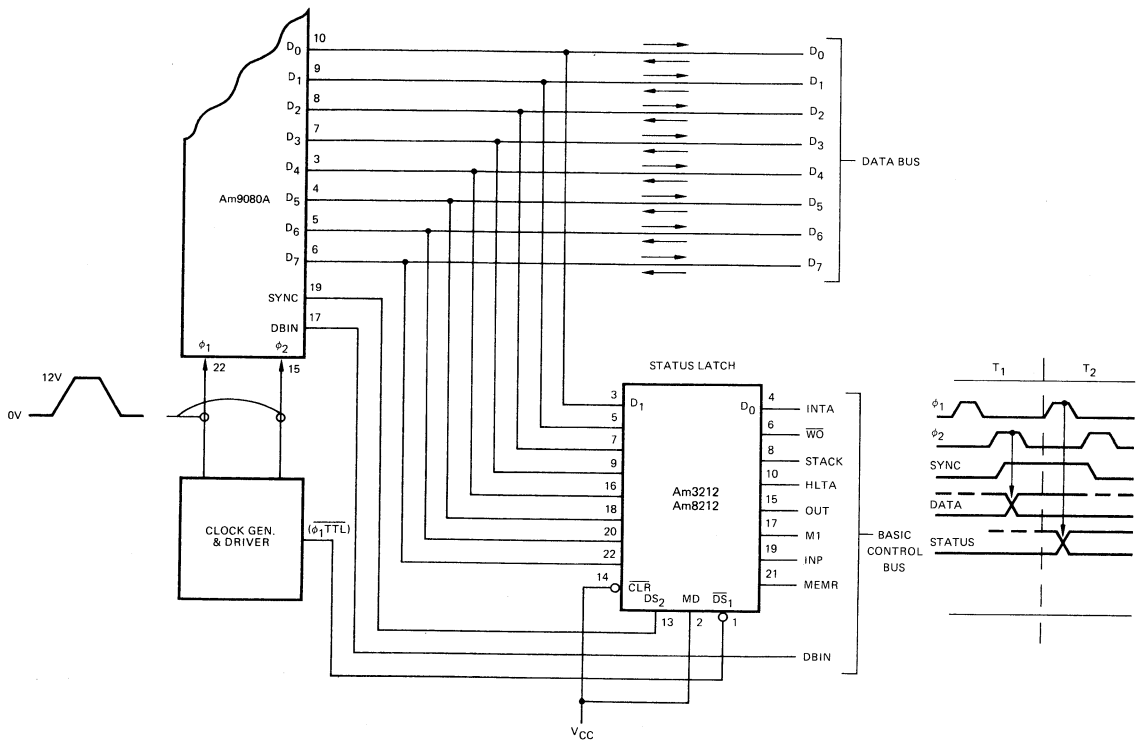
The Am3212 • Am8212 is used to transmit data from the data bus to a system output. The output strobe could be a hand-shaking signal such as "reception of data" from the device that the system is outputting to. It in turn, can interrupt the system signifying the reception of date. The selection of the port comes from the device selection logic. ($\overline{DS}_1 \cdot \overline{DS}_2$).



Am9080A Status Latch

The input to the Am3212 • Am8212 latch comes directly from the Am9080A data bus. Timing shows that when the SYNC signal is true (\overline{DS}_1 input), and ϕ_1 is true,

(\overline{DS}_1 input) then the status data will be latched into the Am3212 • Am8212. The mode signal is tied high so that the output on the latch is active and enabled all the time.



Am8T26

Schottky Three-State Quad Bus Driver/Receiver

Distinctive Characteristics

- Advanced Schottky technology
- 40mA driver sink current
- Three-state outputs on driver and receiver
- PNP inputs
- 20ns max. driver propagation delay
- 18ns max. receiver propagation delay
- 100% reliability assurance testing in compliance with MIL-STD-883

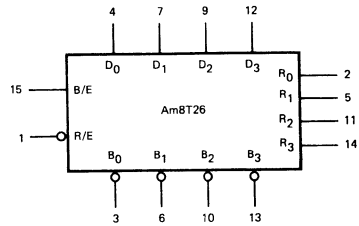
FUNCTIONAL DESCRIPTION

The Am8T26 is a high speed bus transceiver consisting of four bus drivers with three-state outputs and four bus receivers, also with three-state outputs. Each driver output is internally connected to a receiver input. Both the drivers and receivers have PNP inputs.

One buffered common "bus enable" input is connected to the four drivers and another buffered common "receiver enable" input is connected to the receivers. A LOW on the bus enable (B/E) input forces the four driver outputs to the high-impedance state. A HIGH on the bus enable allows input data to be transferred onto the data bus.

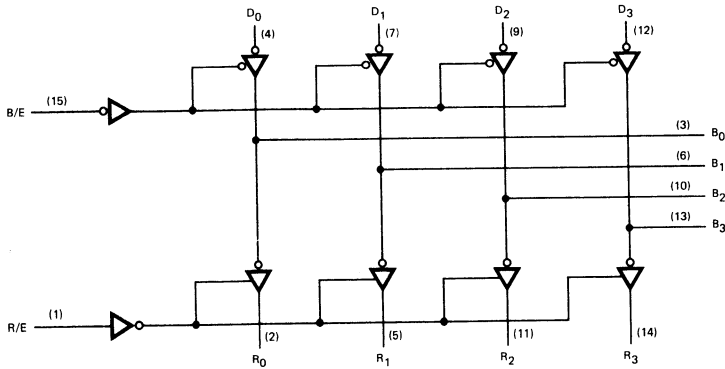
A HIGH on the receiver enable (R/E) input forces the four receiver outputs to the high-impedance state while a LOW on the receiver enable input allows the received data to be transferred to the output. The complementary design of the bus enable and receiver enable inputs allows these control inputs to be connected together externally such that a single transmit/receive function is derived.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

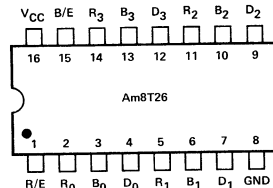
LOGIC DIAGRAM



ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +75°C	N8T26B
Hermetic DIP	0°C to +75°C	N8T26F
Dice	0°C to +75°C	AM8T26XC
Hermetic DIP	-55°C to +125°C	S8T26F
Dice	-55°C to +125°C	AM8T26XM

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

Am8T26

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

N8T26 T_A = 0°C to +75°C
 S8T26 T_A = -55°C to +125°C V_{CC} = 5.0V ±5% MIN. = 4.75V MAX. = 5.25V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Driver Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -10mA V _{IN} = V _{IH} or V _{IL}	2.6	3.1		Volts
V _{OL}	Driver Output LOW Voltage	V _{CC} = MIN., I _{OL} = 40mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts
V _{OH}	Receiver Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -2mA V _{IN} = V _{IH} or V _{IL}	2.6	3.1		Volts
V _{OL}	Receiver Output LOW Voltage	V _{CC} = MIN., I _{OL} = -16mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.85	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -5mA			-1.0	Volts
I _{IL} (Note 3)	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.4V			-0.2	mA
I _{IH} (Note 3)	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.25V			25	μA
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 0.0V				
		Driver	-50		-150	mA
		Receiver	-30		-75	
I _{CC}	Power Supply Current	V _{CC} = MAX.			87	mA
I _O	Bus Leakage Current with Driver Off	V _{CC} = MAX., V _{BUS} = 2.6V V _{IN} = V _{IH} or V _{IL}			100	μA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
 4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

Switching Characteristics (T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	Driver Input to Bus	Figure 1		16	20	ns
t _{PHL}				16	20	
t _{PLH}	Bus to Receiver Output	Figure 2		13	18	ns
t _{PHL}				6	10	
t _{ZL}	Driver Enable to Bus	Figure 3		29	38	ns
t _{LZ}				35	43	
t _{ZL}	Receiver Enable to Receiver Output	Figure 4		20	30	ns
t _{LZ}				10	17	

DEFINITION OF FUNCTIONAL TERMS

D₀, D₁, D₂, D₃ The four driver inputs.

B₀, B₁, B₂, B₃ The four driver outputs and receiver inputs (data is inverted).

R₀, R₁, R₂, R₃ The four receiver outputs. Data from the bus is inverted while data from the driver inputs is non-inverted.

B/E Bus enable input. When the bus enable input is LOW, the four driver outputs are in the high-impedance state.

R/E Receiver enable input. When the receiver enable input is HIGH, the four receiver outputs are in the high-impedance state.

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	LOW Input Unit Load	Fan-out Output HIGH	Output LOW
R/E	1	1/8	—	—
R ₀	2	—	50	10
B ₀	3	1/16	250	25
D ₀	4	1/8	—	—
R ₁	5	—	50	10
B ₁	6	1/16	250	25
D ₁	7	1/8	—	—
GND	8	—	—	—
D ₂	9	1/8	—	—
B ₂	10	1/16	250	25
R ₂	11	—	50	10
D ₃	12	1/8	—	—
B ₃	13	1/16	250	25
R ₃	14	—	50	10
B/E	15	1/8	—	—
V _{CC}	16	—	—	—

A TTL Unit Load is defined as -1.6mA measured at 0.4V LOW and $40\mu\text{A}$ measured at 2.4V HIGH.

DRIVER FUNCTION TABLE

INPUTS		OUTPUT
B/E	D _i	B _j
L	X	Z
H	L	H
H	H	L

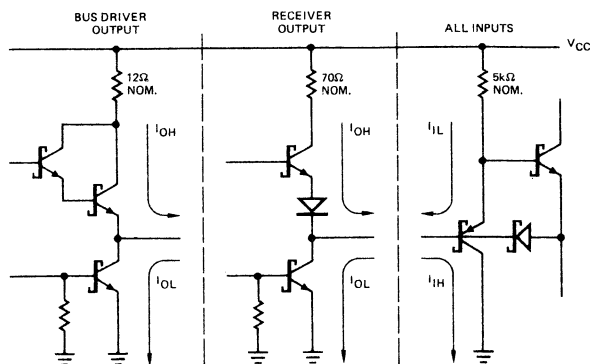
L = LOW
H = HIGH
X = Don't Care
Z = High Impedance
i = 0, 1, 2, or 3

RECEIVER FUNCTION TABLE

INPUTS		OUTPUT
R/E	B _j	R _i
H	X	Z
L	L	H
L	H	L

L = LOW
H = HIGH
X = Don't Care
Z = High Impedance
i = 0, 1, 2, or 3

INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

AC TEST CIRCUITS AND WAVEFORMS

PROPAGATION DELAY (Data In to Bus)

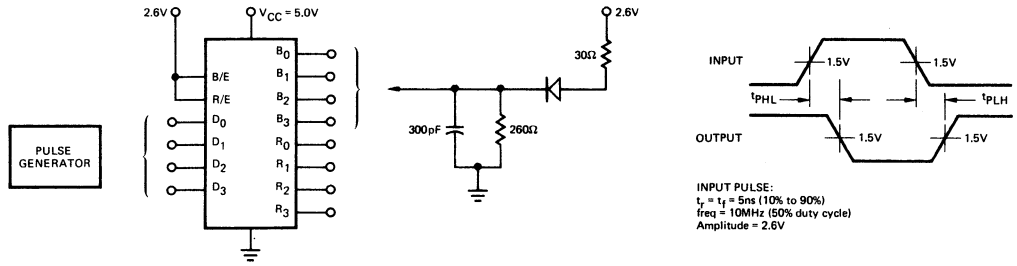


Figure 1

PROPAGATION DELAY (Bus to Receiver Out)

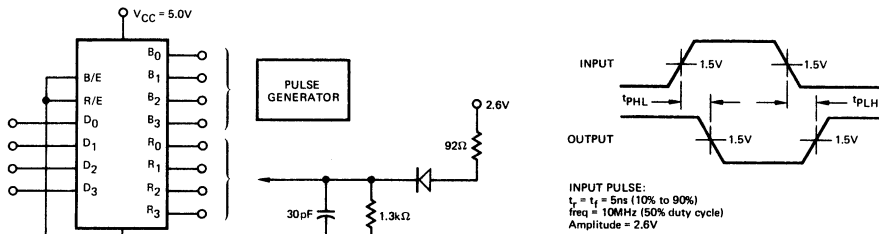


Figure 2

PROPAGATION DELAY (Bus Enable to Bus Output)

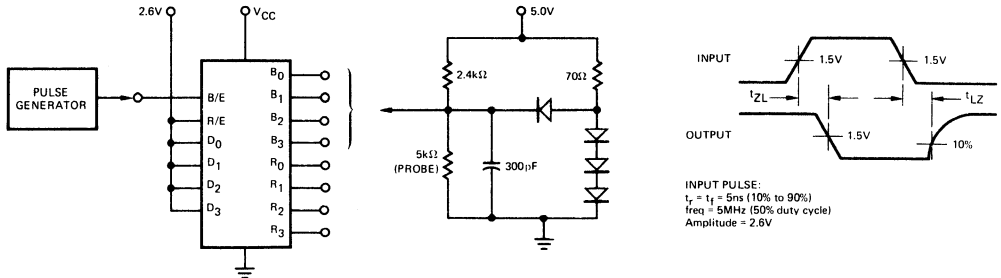


Figure 3

PROPAGATION DELAY (Receive Enable to Receive Output)

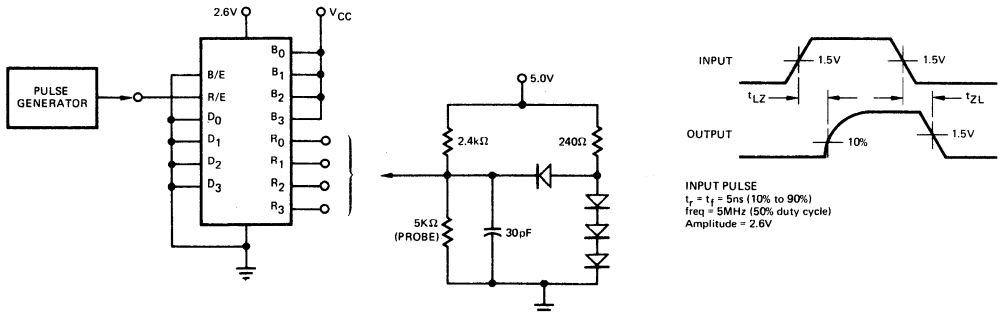
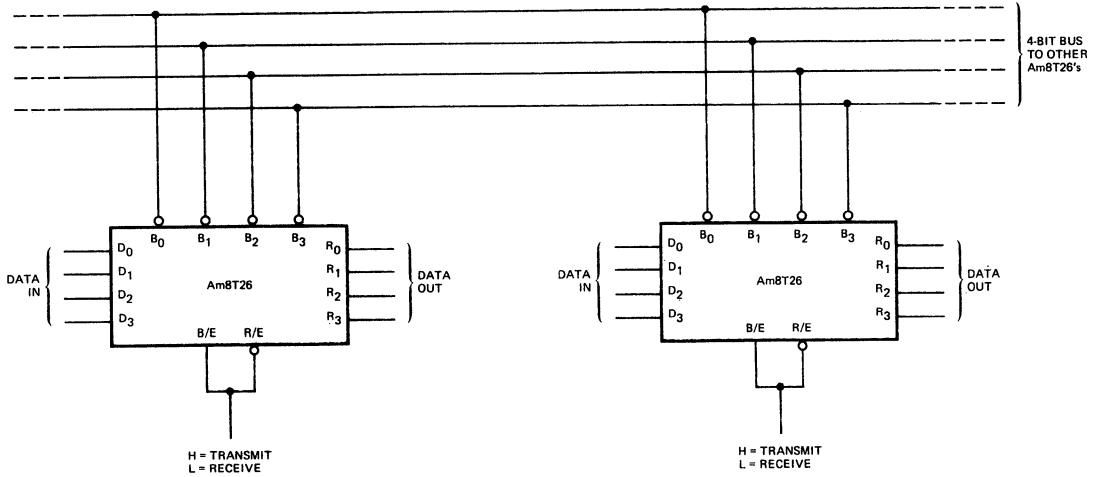
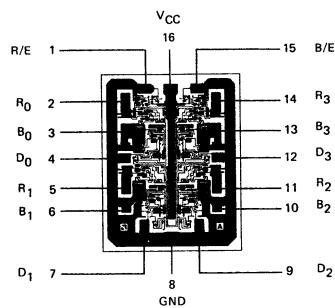


Figure 4

APPLICATION



Metallization and Pad Layout



DIE SIZE 0.063" X 0.082"

Am8T26A·Am8T28

Schottky Three-State Quad Bus Driver/Receiver

Distinctive Characteristics

- Advanced Schottky technology
- 48mA driver sink current
- Three-state outputs on driver and receiver
- PNP inputs
- Am8T26A has inverting outputs
- Am8T28 has non-inverting outputs
- Driver propagation delay – 14ns max. for 8T26A; 17ns max. for 8T28
- Receiver propagation delay – 14ns max. for 8T26A; 17ns max. for 8T28
- 100% reliability assurance testing in compliance with MIL-STD-883

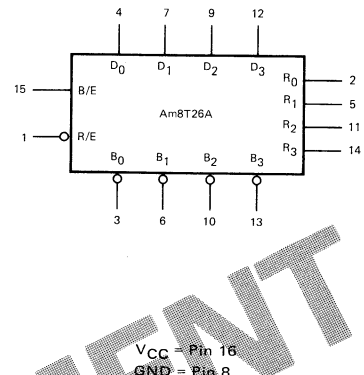
FUNCTIONAL DESCRIPTION

The Am8T26A/Am8T28 are high speed bus transceivers consisting of four bus drivers with three-state outputs and four bus receivers, also with three-state outputs. Each driver output is internally connected to a receiver input. Both the drivers and receivers have PNP inputs.

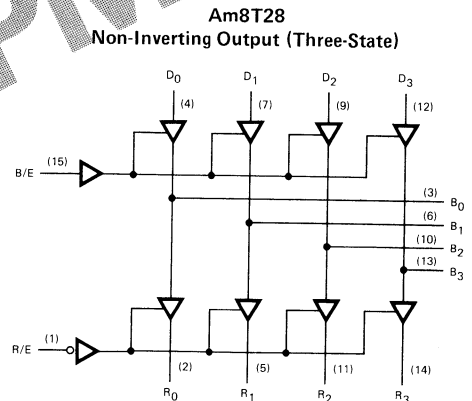
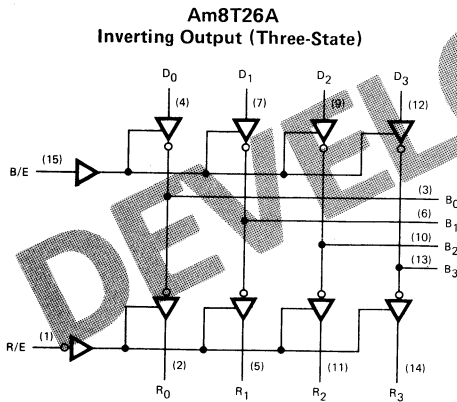
One buffered common "bus enable" input is connected to the four drivers and another buffered common "receiver enable" input is connected to the receivers. A LOW on the bus enable (B/E) input forces the four driver outputs to the high-impedance state. A HIGH on the bus enable allows input data to be transferred onto the data bus.

A HIGH on the receiver enable (R/E) input forces the four receiver outputs to the high-impedance state while a LOW on the receiver enable input allows the received data to be transferred to the output. The complementary design of the bus enable and receiver enable inputs allows these control inputs to be connected together externally such that a single transmit/receive function is derived.

LOGIC SYMBOL



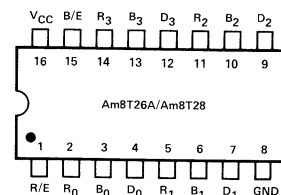
LOGIC DIAGRAMS



ORDERING INFORMATION

Package Type	Temperature Range	Am8T26A	Am8T28
		Order Number	Order Number
Molded DIP	0°C to +75°C	N8T26AB	N8T28B
Hermetic DIP	0°C to +75°C	N8T26AF	N8T28F
Dice	0°C to +75°C	AM8T26AXC	AM8T28XC
Hermetic DIP	-55°C to +125°C	S8T26AF	S8T28F
Dice	-55°C to +125°C	AM8T26AXM	AM8T28XM

CONNECTION DIAGRAM (Top View)



Note: Pin 1 is marked for orientation.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs (Receiver)	30mA
DC Output Current, Into Outputs (BUS)	80mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

The Following Conditions Apply Unless Otherwise Noted:

N8T26A, N8T28 T_A = 0°C to +75°C (COM'L) MIN. = 4.75 V MAX. = 5.25 VS8T26A, S8T28 T_A = -55°C to +125°C (MIL) MIN. = 4.50 V MAX. = 5.50 V**DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE**

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
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Driver

I _{IL}	Low Level Input Current	V _{IN} = 0.4 V			-200	μA
I _{IL}	Low Level Input Current (Disabled)	V _{IN} = 0.4 V			-25	μA
I _{IH}	High Level Input Current (D _{IN} , D _E)	V _{IN} = V _{CC} MAX.			25	μA
V _{OL}	Low Level Output Voltage	I _{OUT} = 48mA (Note 5)			0.5	Volts
V _{OH}	High Level Output Voltage	I _{OUT} = -10mA, V _{CC} = V _{CC} MIN. (Note 6)	2.4			Volts
I _{OS}	Short Circuit Output Current	V _{OUT} = 0V, V _{CC} = V _{CC} MAX. (Note 4)	-50		-150	mA

Receiver

I _{IL}	Low Level Input Current	V _{IN} = 0.4 V			-200	μA
I _{IH}	High Level Input Current (R _E)	V _{IN} = V _{CC} MAX.			25	μA
V _{OL}	Low Level Output Voltage	I _{OUT} = 20mA (Note 5)			0.5	Volts
V _{OH}	High Level Output Voltage	I _{OUT} = -100μA, V _{CC} = 5.0 V	3.5			Volts
		I _{OUT} = -2.0mA (Note 6)	2.4			
I _{OS}	Short Circuit Output Current	V _{OUT} = 0V, V _{CC} = V _{CC} MAX.	-30		-75	mA

Both Driver and Receiver

V _{TL}	Low Level Input Threshold Voltage		0.85			Volts
V _{TH}	High Level Input Threshold Voltage				2.0	Volts
I _O	Low Level Output Off Leakage Current	V _{OUT} = 0.5 V			-100	μA
	High Level Output Off Leakage Current	V _{OUT} = 2.4 V			100	μA
V _I	Input Clamp Voltage	I _I = -12mA			-1.0	Volts
P _{WR} / I _{CC}	Power/Current Consumption	Am8T26A	V _{CC} = V _{CC} MAX.		457/87	mW/mA
		Am8T28	V _{CC} = V _{CC} MAX.		578/110	

Switching Characteristics (T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description	Test Conditions	Am8T26A			Am8T28			Units
			Min.	Typ.	Max.	Min.	Typ.	Max.	
t _{PLH}	Driver Input to Bus	Figure 1		10	14		13	17	ns
t _{PHL}				10	14		13	17	
t _{PLH}	Bus to Receiver Output	Figure 2		9.0	14		12	17	ns
t _{PHL}				6.0	14		9.0	17	
t _{ZL}	Driver Enable to Bus	Figure 3		19	25		21	28	ns
t _{LZ}				15	20		18	23	
t _{ZL}	Receiver Enable to Receiver Output	Figure 4		15	20		18	23	ns
t _{LZ}				10	15		13	18	

Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.

3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).

4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

5. Output sink current is supplied through a resistor to V_{CC}.

6. Measurements apply to each output and the associated data input independently.

DEFINITION OF FUNCTIONAL TERMS

D₀, D₁, D₂, D₃ The four driver inputs.

B₀, B₁, B₂, B₃ The four driver outputs and receiver inputs (data is inverted).

R₀, R₁, R₂, R₃ The four receiver outputs. Data from the bus is inverted while data from the driver inputs is non-inverted.

B/E Bus enable input. When the bus enable input is LOW, the four driver outputs are in the high-impedance state.

R/E Receiver enable input. When the receiver enable input is HIGH, the four receiver outputs are in the high-impedance state.

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	LOW Input Unit Load	Fan-out	
			Output HIGH	Output LOW
R/E	1	1/8	—	—
R ₀	2	—	50	10
B ₀	3	1/16	250	25
D ₀	4	1/8	—	—
R ₁	5	—	50	10
B ₁	6	1/16	250	25
D ₁	7	1/8	—	—
GND	8	—	—	—
D ₂	9	1/8	—	—
B ₂	10	1/16	250	25
R ₂	11	—	50	10
D ₃	12	1/8	—	—
B ₃	13	1/16	250	25
R ₃	14	—	50	10
B/E	15	1/8	—	—
V _{CC}	16	—	—	—

A TTL Unit Load is defined as -1.6mA measured at 0.4V LOW and 40µA measured at 2.4V HIGH.

DRIVER FUNCTION TABLE

INPUTS		Am8T26A OUTPUT	Am8T28 OUTPUT
B/E	D _i	B _i	B _i
L	X	Z	Z
H	L	H	L
H	H	L	H

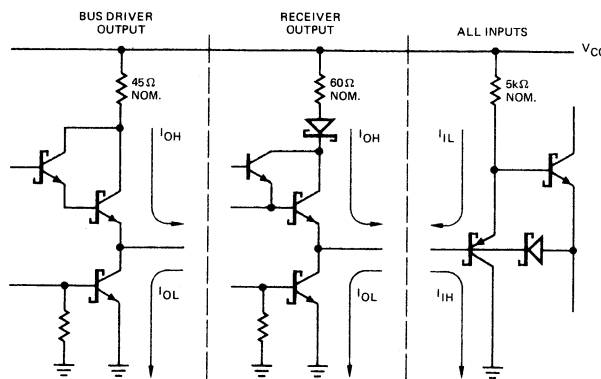
L = LOW
H = HIGH
i = 0, 1, 2, or 3
X = Don't Care
Z = High Impedance

RECEIVER FUNCTION TABLE

INPUTS		Am8T26A OUTPUT	Am8T28 OUTPUT
R/E	B _i	R _i	R _i
H	X	Z	Z
L	L	H	L
L	H	L	H

L = LOW
H = HIGH
i = 0, 1, 2, or 3
X = Don't Care
Z = High Impedance

INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

AC TEST CIRCUITS AND WAVEFORMS

PROPAGATION DELAY (Data In to Bus)

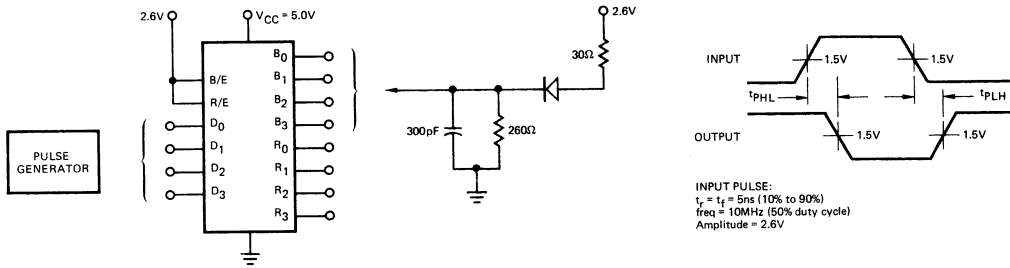


Figure 1

PROPAGATION DELAY (Bus to Receiver Out)

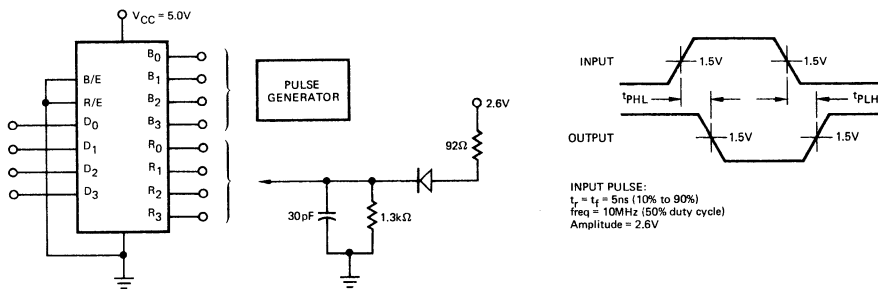


Figure 2

PROPAGATION DELAY (Bus Enable to Bus Output)

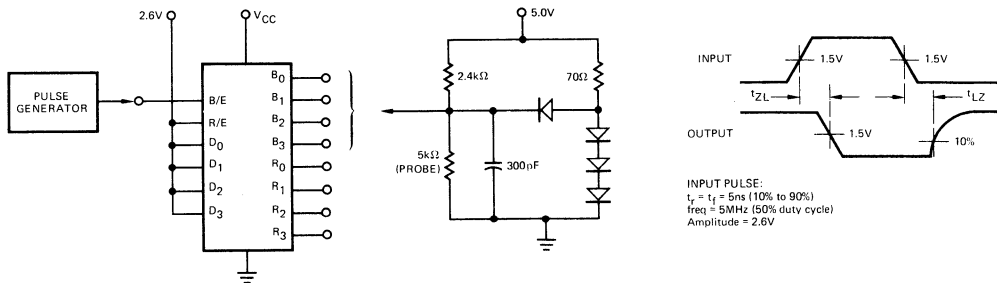


Figure 3

PROPAGATION DELAY (Receive Enable to Receive Output)

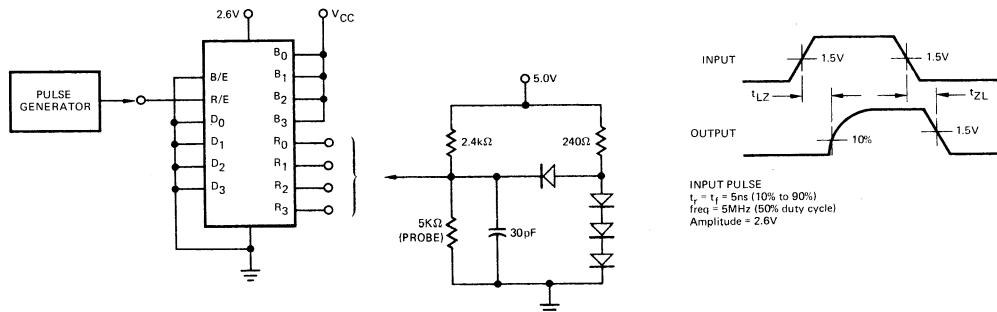
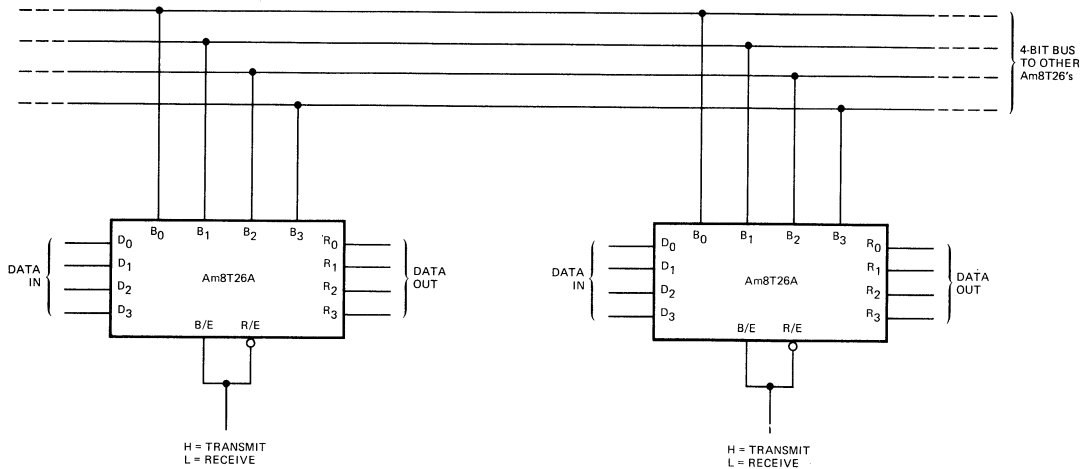


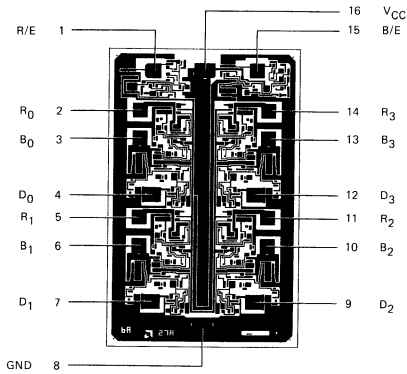
Figure 4

APPLICATION



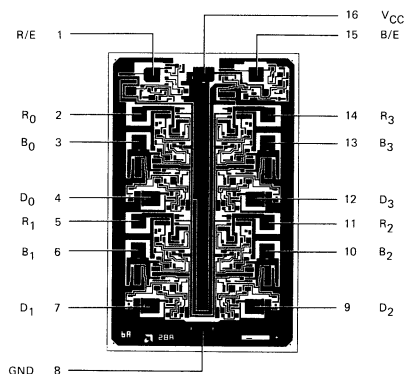
Metallization and Pad Layouts

Am8T26A



DIE SIZE 0.058" X 0.091"

Am8T28



DIE SIZE 0.058" X 0.091"

Am82S62

Nine-Input Parity Checker/Generator

Distinctive Characteristics

- ODD/EVEN parity outputs
- Inhibit input to disable both outputs
- High-speed expansion input – P₉
- PNP inputs
- Advanced Schottky technology
- 100% reliability assurance testing in compliance with MIL-STD-883.

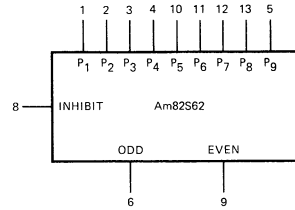
FUNCTIONAL DESCRIPTION

The Am82S62 is a 9-bit parity generator/parity checker with both an ODD parity output and an EVEN parity output. The device can be used to detect errors in data transmission or data retrieval systems as well as to generate this parity check bit.

The Am82S62 features one special high-speed input (P₉) to facilitate expansion. The propagation delay to the outputs through this path is considerably reduced when compared to the P₁ through P₈ paths. This short delay path allows parity checkers/generators of larger size than 9-bits to be built with a minimum of additional delay.

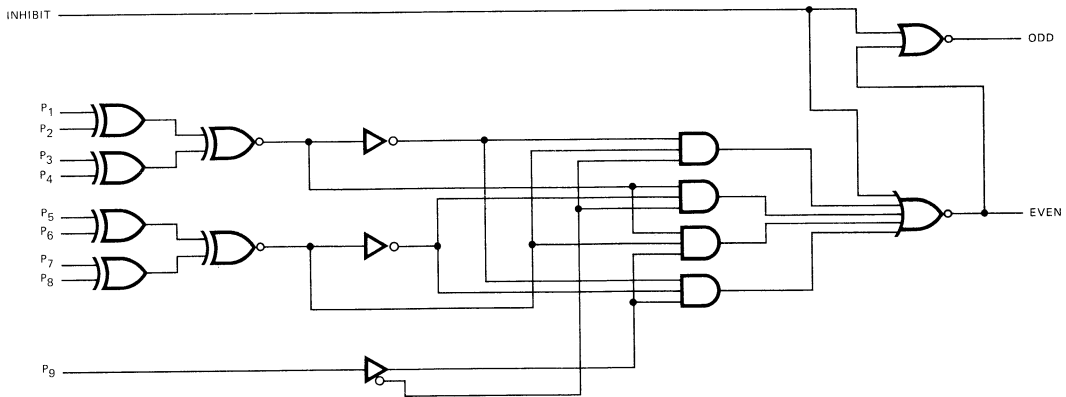
The device is built using advanced Schottky technology and incorporates PNP input transistors to reduce input loading to 0.4 STTL unit loads. The EVEN output is one gate propagation delay time shorter than the ODD output.

LOGIC SYMBOL



V_{CC} = Pin 14
GND = Pin 7

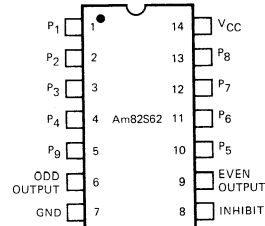
LOGIC DIAGRAM



ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +75°C	N82S62A
Hermetic DIP	0°C to +75°C	N82S62F
Dice	0°C to +75°C	N82S62X
Hermetic DIP	-55°C to +125°C	S82S62F
Dice	-55°C to +125°C	S82S62X

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

Am82S62

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 14 to Pin 7) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless otherwise noted)

N82S62 T_A = 0°C to +75°C V_{CC} = 5.0V ±5% MIN. = 4.75V MAX. = 5.25V
 S82S62 T_A = -55°C to +125°C

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1mA V _{IN} = V _{IH} or V _{IL}	S82	2.5		Volts
			N82	2.7		
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{IL} (Note 3)	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V	P ₉		-0.4	mA
			Others		-0.8	
I _{IH} (Note 3)	Input HIGH Current	V _{CC} = MAX., V _{IN} = 4.5V			10	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 0.0V	-40		-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)			67	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
 4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 5. P₁ through P₉ grounded; inhibit at 4.5V; outputs open.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	P ₁ through P ₈ to Even Output	V _{CC} = 5.0V, R _L = 280Ω, C _L = 15 pF			23	ns
t _{PHL}						
t _{PLH}	P ₁ through P ₈ to Odd Output				28	ns
t _{PHL}						
t _{PLH}	P ₉ to Even Output				12	ns
t _{PHL}						
t _{PLH}	P ₉ to Odd Output				18	ns
t _{PHL}						
t _{PLH}	Inhibit to Even Output				9	ns
t _{PHL}						
t _{PLH}	Inhibit to Odd Output			9	ns	
t _{PHL}						

TRUTH TABLE

INHIBIT	NUMBER OF P INPUTS		OUTPUT	
	LOW	HIGH	ODD	EVEN
L	0	9	H	L
L	1	8	L	H
L	2	7	H	L
L	3	6	L	H
L	4	5	H	L
L	5	4	L	H
L	6	3	H	L
L	7	2	L	H
L	8	1	H	L
L	9	0	L	H
H	X	X	L	L

H = HIGH
L = LOW
X = Don't Care

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
P ₁	1	0.4	—	—
P ₂	2	0.4	—	—
P ₃	3	0.4	—	—
P ₄	4	0.4	—	—
P ₉	5	0.2	—	—
ODD	6	—	20	10
GND	7	—	—	—
INHIBIT	8	0.4	—	—
EVEN	9	—	20	10
P ₅	10	0.4	—	—
P ₆	11	0.4	—	—
P ₇	12	0.4	—	—
P ₈	13	0.4	—	—
V _{CC}	14	—	—	—

A Schottky TTL Unit Load is defined as 50 μ A measured at 2.7V HIGH and -2.0mA measured at 0.5V LOW.

DEFINITION OF FUNCTIONAL TERMS

P₁ through P₉ The nine inputs to the parity tree.

INHIBIT A HIGH on the inhibit input forces both the odd output and even output LOW regardless of the P inputs. When the inhibit is LOW, the odd and even outputs will always be of opposite phase.

ODD The odd parity output of the device. When an odd number of P inputs are at a HIGH level, the odd output will be HIGH.

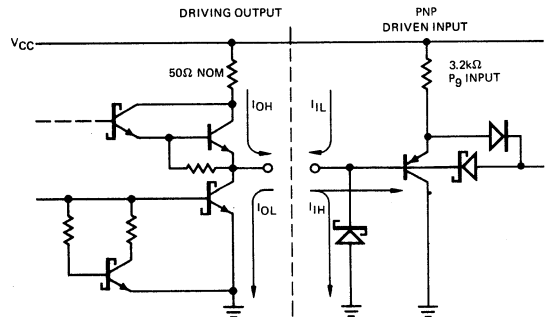
EVEN The even parity output of the device. When an even number of P inputs are at a HIGH level, the even output will be HIGH.

LOGIC EQUATIONS

$$\text{ODD Output} = P_1 \oplus P_2 \oplus P_3 \oplus P_4 \oplus P_5 \oplus P_6 \oplus P_7 \oplus P_8 \oplus P_9$$

$$\text{EVEN Output} = P_1 \oplus P_2 \oplus P_3 \oplus P_4 \oplus P_5 \oplus P_6 \oplus P_7 \oplus P_8 \oplus P_9$$

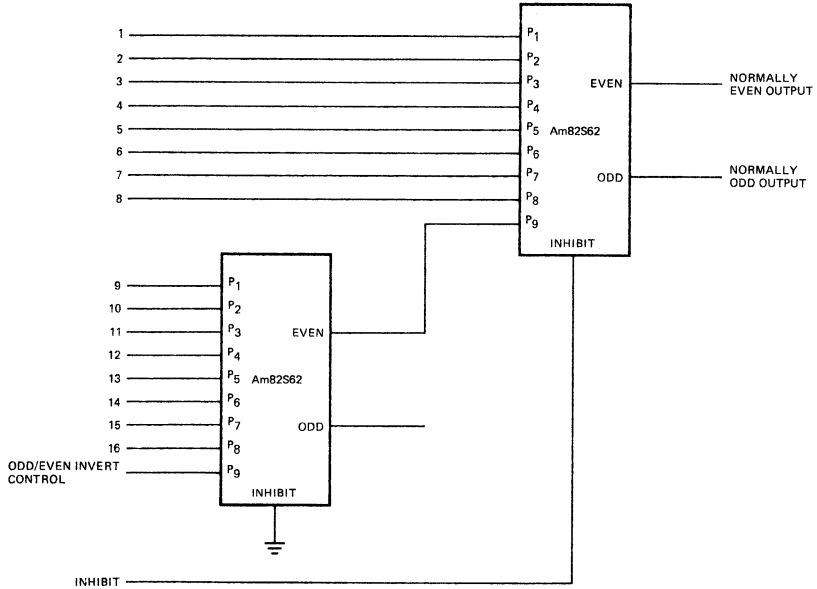
SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



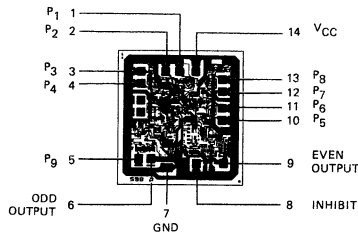
Note: Actual current flow direction shown.

APPLICATION

16-BIT PARITY GENERATOR WITH INVERT CONTROL



Metallization and Pad Layout



DIE SIZE 0.067" X 0.072"

Am73/8304B

Octal Three-State Bidirectional Transceiver

DISTINCTIVE CHARACTERISTICS

- 8-bit bidirectional data flow reduces system package count
- Three-state inputs/outputs for interfacing with bus-oriented systems
- PNP inputs reduce input loading
- $V_{CC} - 1.15V$ V_{OH} interfaces with TTL, MOS, and CMOS
- 48mA, 300pF bus drive capability
- Transmit/Receive and Chip Disable simplify control logic
- 20 pin ceramic and molded DIP package
- Low power – 8mA per bidirectional bit
- Advanced Schottky processing
- Bus port stays in hi-impedance state during power up/down
- 100% product assurance screening to MIL-STD-883 requirements

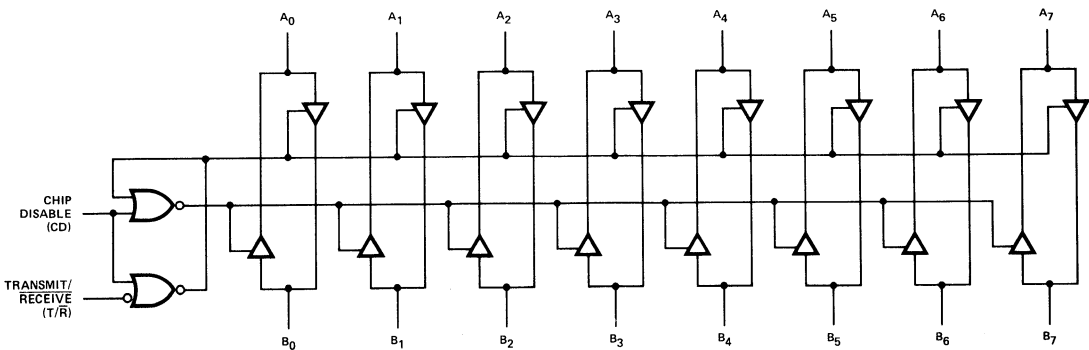
GENERAL DESCRIPTION

The Am73/8304Bs are 8-bit three-state Schottky transceivers. They provide bidirectional drive for bus-oriented microprocessor and digital communications systems. Straight through bidirectional transceivers are featured, with 16mA drive capability on the A ports and 48mA bus drive capability on the B ports. PNP inputs are incorporated to reduce input loading.

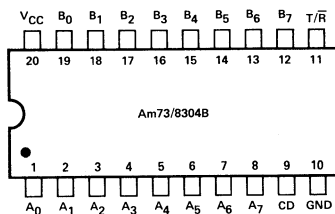
One input, Transmit/Receive determines the direction of logic signals through the bidirectional transceiver. The Chip Disable input disables both A and B ports by placing them in a three-state condition.

The output high voltage (V_{OH}) is specified at $V_{CC} - 1.15V$ minimum to allow interfacing with MOS, CMOS, TTL, ROM, RAM, or microprocessors.

LOGIC DIAGRAM

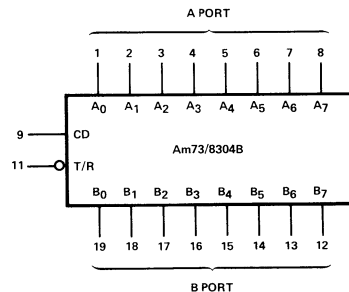


CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



V_{CC} = Pin 20
GND = Pin 10

Am8304B

ABSOLUTE MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Supply Voltage	7.0V
Input Voltage	5.5V
Output Voltage	5.5V
Lead Temperature (Soldering, 10 seconds)	300°C

ELECTRICAL CHARACTERISTICS

The Following Conditions Apply Unless Otherwise Noted:

Am7304B	$T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$	$V_{CC\text{MIN}} = 4.5\text{V}$	$V_{CC\text{MAX}} = 5.5\text{V}$
Am8304B	$T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$	$V_{CC\text{MIN}} = 4.75\text{V}$	$V_{CC\text{MAX}} = 5.25\text{V}$

DC ELECTRICAL CHARACTERISTICS over operating temperature range

Parameters	Description	Test Conditions	Min.	Typ. (Note 1)	Max.	Units	
A PORT (A₀-A₇)							
V _{IH}	Logical "1" Input Voltage	CD = 0.8V, T/R = 2.0V	2.0			Volts	
V _{IL}	Logical "0" Input Voltage	CD = 0.8V, T/R = 2.0V			0.8 0.7	Volts	
V _{OH}	Logical "1" Output Voltage	CD = 0.8V, T/R = 0.8V		V _{CC} -1.15 2.7	V _{CC} -0.7 3.95	Volts	
V _{OL}	Logical "0" Output Voltage	CD = 0.8V, T/R = 0.8V			0.3 0.35	0.4 0.50	Volts
I _{OS}	Output Short Circuit Current	CD = 0.8V, T/R = 0.8V, V _O = 0V, V _{CC} = MAX., Note 2	-10	-38	-75	mA	
I _{IH}	Logical "1" Input Current	CD = 0.8V, T/R = 2.0V, V _I = 2.7V		0.1	80	μA	
I _I	Input Current at Maximum Input Voltage	CD = 2.0V, V _{CC} = MAX., V _I = V _{CC} MAX.			1	mA	
I _{IL}	Logical "0" Input Current	CD = 0.8V, T/R = 2.0V, V _I = 0.4V		-70	-200	μA	
V _C	Input Clamp Voltage	CD = 2.0V, I _{IN} = -12mA		-0.7	-1.5	Volts	
I _{OD}	Output/Input Three-State Current	CD = 2.0V			-200 80	μA	
B PORT (B₀-B₇)							
V _{IH}	Logical "1" Input Voltage	CD = 0.8V, T/R = 0.8V	2.0			Volts	
V _{IL}	Logical "0" Input Voltage	CD = 0.8V, T/R = 0.8V			0.8 0.7	Volts	
V _{OH}	Logical "1" Output Voltage	CD = 0.8V, T/R = 2.0V		V _{CC} -1.15 2.7	V _{CC} -0.8 3.9	Volts	
V _{OL}	Logical "0" Output Voltage	CD = 0.8V, T/R = 2.0V			0.3 0.4	0.4 0.5	Volts
I _{OS}	Output Short Circuit Current	CD = 0.8V, T/R = 2.0V, V _O = 0V, V _{CC} = MAX., Note 2	-25	-50	-150	mA	
I _{IH}	Logical "1" Input Current	CD = 0.8V, T/R = 0.8V, V _I = 2.7V		0.1	80	μA	
I _I	Input Current at Maximum Input Voltage	CD = 2.0V, V _{CC} = MAX., V _I = V _{CC} MAX.			1	mA	
I _{IL}	Logical "0" Input Current	CD = 0.8V, T/R = 0.8V, V _I = 0.4V		-70	-200	μA	
V _C	Input Clamp Voltage	CD = 2.0V, I _{IN} = -12mA		-0.7	-1.5	Volts	
I _{OD}	Output/Input Three-State Current	CD = 2.0V			-200 200	μA	
CONTROL INPUTS CD, T/R							
V _{IH}	Logical "1" Input Voltage		2.0			Volts	
V _{IL}	Logical "0" Input Voltage				0.8	Volts	
I _{IH}	Logical "1" Input Current	V _I = 2.7V		0.5	20	μA	
I _I	Input Current at Maximum Input Voltage	V _{CC} = MAX., V _I = V _{CC} MAX.			1.0	mA	
I _{IL}	Logical "0" Input Current	V _I = 0.4V		-0.1 -0.25	-0.25 -0.5	0.1 0.25	mA
V _C	Input Clamp Voltage	I _{IN} = -12mA		-0.8	-1.5	Volts	
POWER SUPPLY CURRENT							
I _{CC}	Power Supply Current	CD = 2.0V, V _{CC} = MAX., V _{IN} = 0.4V		60	100	mA	
		CD = V _{INA} = 0.4V, T/R = 2V, V _{CC} = MAX.		80	130		

AC ELECTRICAL CHARACTERISTICS ($V_{CC} = 5.0V$, $T_A = 25^\circ C$)

Parameters	Description	Test Conditions	Min.	Typ. (Note 1)	Max.	Units
A PORT DATA/MODE SPECIFICATIONS						
t_{PDHLA}	Propagation Delay to a Logical "0" from B Port to A Port	$CD = 0.4V$, $T/\bar{R} = 0.4V$ (Figure 1) $R_1 = 1k$, $R_2 = 5k$, $C_1 = 30pF$		14	18	ns
t_{PDLHA}	Propagation Delay to a Logical "1" from B Port to A Port	$CD = 0.4V$, $T/\bar{R} = 0.4V$ (Figure 1) $R_1 = 1k$, $R_2 = 5k$, $C_1 = 30pF$		13	18	ns
t_{PLZA}	Propagation Delay from a Logical "0" to Three-State from CD to A Port	B_0 to $B_7 = 0.4V$, $T/\bar{R} = 0.4V$ (Figure 3) $S_3 = 1$, $R_5 = 1k$, $C_4 = 15pF$		11	15	ns
t_{PHZA}	Propagation Delay from a Logical "1" to Three-State from CD to A Port	B_0 to $B_7 = 2.4V$, $T/\bar{R} = 0.4V$ (Figure 3) $S_3 = 0$, $R_5 = 1k$, $C_4 = 15pF$		8	15	ns
t_{PZLA}	Propagation Delay from Three-State to a Logical "0" from CD to A Port	B_0 to $B_7 = 0.4V$, $T/\bar{R} = 0.4V$ (Figure 3) $S_3 = 1$, $R_5 = 1k$, $C_4 = 30pF$		27	35	ns
t_{PZHA}	Propagation Delay from Three-State to a Logical "1" from CD to A Port	B_0 to $B_7 = 2.4V$, $T/\bar{R} = 0.4V$ (Figure 3) $S_3 = 0$, $R_5 = 5k$, $C_4 = 30pF$		19	25	ns
B PORT DATA/MODE SPECIFICATIONS						
t_{PDHLB}	Propagation Delay to a Logical "0" from A Port to B Port	$CD = 0.4V$, $T/\bar{R} = 2.4V$ (Figure 1) $R_1 = 100\Omega$, $R_2 = 1k$, $C_1 = 300pF$		18	23	ns
		$R_1 = 667\Omega$, $R_2 = 5k$, $C_1 = 45pF$		11	18	
t_{PDLHB}	Propagation Delay to a Logical "1" from A Port to B Port	$CD = 0.4V$, $T/\bar{R} = 2.4V$ (Figure 1) $R_1 = 100\Omega$, $R_2 = 1k$, $C_1 = 300pF$		16	23	ns
		$R_1 = 667\Omega$, $R_2 = 5k$, $C_1 = 45pF$		11	18	
t_{PLZB}	Propagation Delay from a Logical "0" to Three-State from CD to B Port	A_0 to $A_7 = 0.4V$, $T/\bar{R} = 2.4V$ (Figure 3) $S_3 = 1$, $R_5 = 1k$, $C_4 = 15pF$		13	18	ns
t_{PHZB}	Propagation Delay from a Logical "1" to Three-State from CD to B Port	A_0 to $A_7 = 2.4V$, $T/\bar{R} = 2.4V$ (Figure 3) $S_3 = 0$, $R_5 = 1k$, $C_4 = 15pF$		8	15	ns
t_{PZLB}	Propagation Delay from Three-State to a Logical "0" from CD to B Port	A_0 to $A_7 = 0.4V$, $T/\bar{R} = 2.4V$ (Figure 3) $S_3 = 1$, $R_5 = 100\Omega$, $C_4 = 300pF$		32	40	ns
		$S_3 = 1$, $R_5 = 667\Omega$, $C_4 = 45pF$		16	22	
t_{PZHB}	Propagation Delay from Three-State to a Logical "1" from CD to B Port	A_0 to $A_7 = 2.4V$, $T/\bar{R} = 2.4V$ (Figure 3) $S_3 = 0$, $R_5 = 1k$, $C_4 = 300pF$		26	35	ns
		$S_3 = 0$, $R_5 = 667\Omega$, $C_4 = 45pF$		14	22	
TRANSMIT RECEIVE MODE SPECIFICATIONS						
t_{PHZR}	Propagation Delay from a Logical "1" to Three-State from T/\bar{R} to A Port	$CD = 0.4V$ (Figure 2) $S_1 = 1$, $R_4 = 100\Omega$, $C_3 = 300pF$ $S_2 = 0$, $R_3 = 1k$, $C_2 = 15pF$		7	12	ns
t_{PLZR}	Propagation Delay from a Logical "0" to Three-State from T/\bar{R} to A Port	$CD = 0.4V$ (Figure 2) $S_1 = 0$, $R_4 = 1k$, $C_3 = 300pF$ $S_2 = 1$, $R_3 = 1k$, $C_2 = 15pF$		10	14	ns
t_{PHZT}	Propagation Delay from a Logical "1" to Three-State from T/\bar{R} to B Port	$CD = 0.4V$ (Figure 2) $S_1 = 0$, $R_4 = 1k$, $C_3 = 15pF$ $S_2 = 1$, $R_3 = 5k$, $C_2 = 30pF$		16	22	ns
t_{PLZT}	Propagation Delay from a Logical "0" to Three-State from T/\bar{R} to B Port	$CD = 0.4V$ (Figure 2) $S_1 = 1$, $R_4 = 1k$, $C_3 = 15pF$ $S_2 = 0$, $R_3 = 1k$, $C_2 = 30pF$		17	22	ns
t_{PRL}	Propagation Delay from Transmit Mode to a Logical "0", T/\bar{R} to A Port	$t_{PRL} = t_{PHZT} + t_{PDHLA}$		25	40	ns
t_{PRH}	Propagation Delay from Transmit Mode to a Logical "1", T/\bar{R} to A Port	$t_{PRH} = t_{PLZT} + t_{PDLHA}$		30	40	ns
t_{PTL}	Propagation Delay from Receive Mode to a Logical "0", T/\bar{R} to B Port	$t_{PTL} = t_{PHZR} + t_{PDHLB}$		25	35	ns
t_{PTH}	Propagation Delay from Receive Mode to a Logical "1", T/\bar{R} to B Port	$t_{PTH} = t_{PLZR} + t_{PDLHB}$		26	35	ns

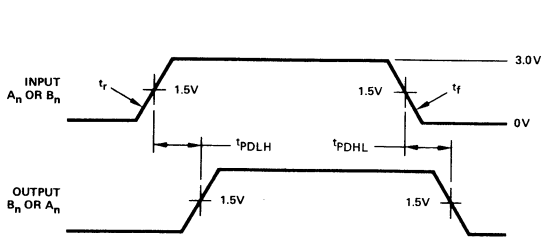
Notes: 1. All typical values given are for $V_{CC} = 5.0V$ and $T_A = 25^\circ C$.

2. Only one output at a time should be shorted.

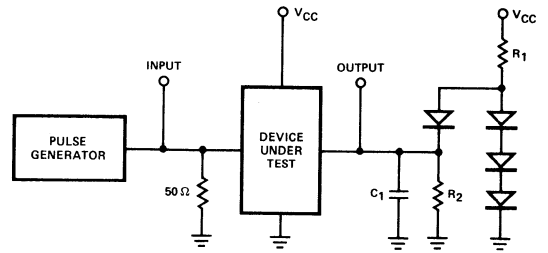
FUNCTIONAL TABLE

Inputs	Conditions		
Chip Disable	0	0	1
Transmit/Receive	0	1	X
A Port	Out	In	Hi-Z
B Port	In	Out	Hi-Z

SWITCHING TIME WAVEFORMS AND AC TEST CIRCUITS

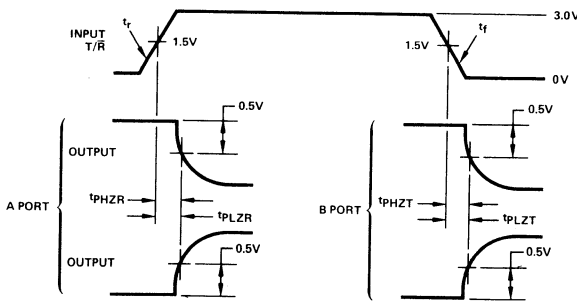


$t_r = t_f < 10\text{ns}$
10% to 90%

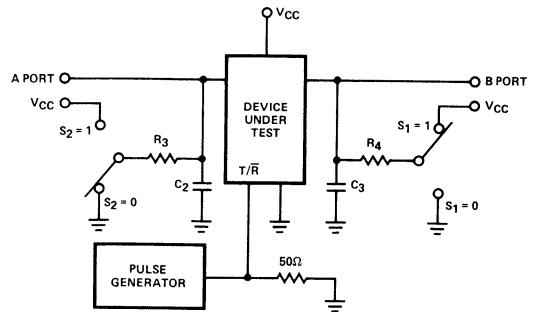


Note: C_1 includes test fixture capacitance.

Figure 1. Propagation Delay from A Port to B Port or from B Port to A Port.

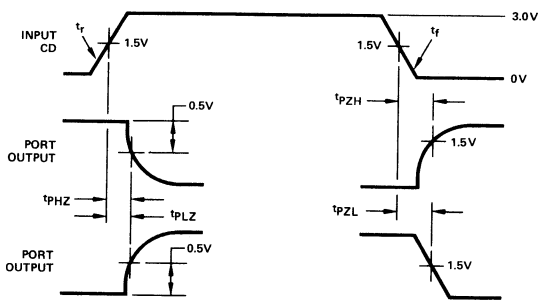


$t_r = t_f < 10\text{ns}$
10% to 90%

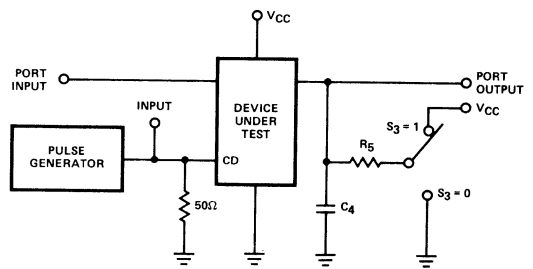


Note: C_2 and C_3 include test fixture capacitance.

Figure 2. Propagation Delay from T/R to A Port or B Port.



$t_r = t_f < 10\text{ns}$
10% to 90%



Note: C_4 includes test fixture capacitance.
Port input is in a fixed logical condition.

Figure 3. Propagation Delay from CD to A Port or B Port.

Am93S10 • Am93S16

BCD Decade/Four-Bit Binary Counters

Distinctive Characteristics

- Fully synchronous counting
- Fully synchronous parallel loading

- Edge-triggered clock action
- Advanced Schottky technology
- 100% reliability assurance testing in compliance with MIL-STD-883.

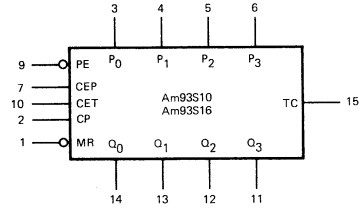
FUNCTIONAL DESCRIPTION

The Am93S10 and Am93S16 are fully synchronous 4-bit decimal and binary counters. With the parallel enable (PE) LOW, data on the P₀-P₃ inputs is parallel loaded on the positive clock transition. When PE is HIGH and both count enables CEP and CET are also HIGH, counting will occur on the LOW-to-HIGH clock transition.

The terminal count state (1001 for the Am93S10 and 1111 for the Am93S16) is decoded and ANDed with CET in the terminal count (TC) output. If CET is HIGH and the counter is in its terminal count state, then TC is HIGH.

Both counters have an asynchronous master reset (\overline{MR}). A LOW on the \overline{MR} input forces the Q outputs LOW independent of all other inputs. The only requirements on the \overline{PE} , CEP, CET and P₀-P₃ inputs is that they meet the set-up time requirements before the clock LOW-to-HIGH transition.

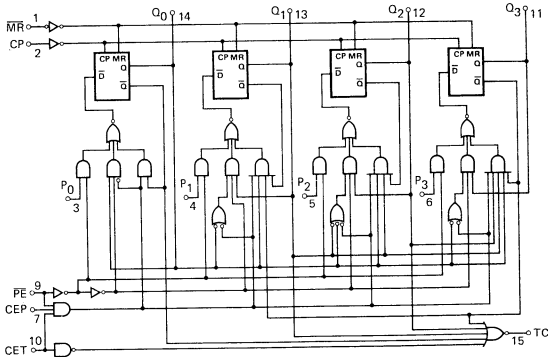
LOGIC SYMBOL



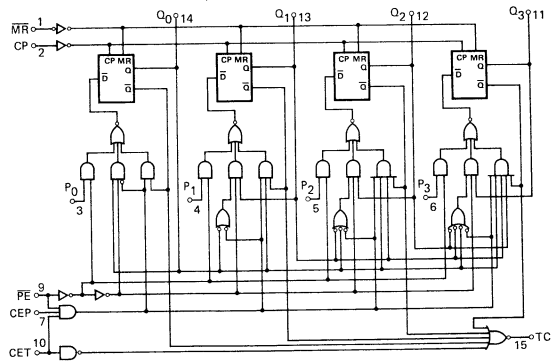
VCC = Pin 16
GND = Pin 8

LOGIC DIAGRAMS

Am93S10



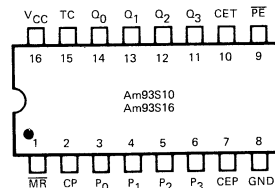
Am93S16



ORDERING INFORMATION

Package Type	Temperature Range	Am93S10 Order Number	Am93S16 Order Number
Molded DIP	0° C to +75° C	93S10PC	93S16PC
Hermetic DIP	0° C to +75° C	93S10DC	93S16DC
Dice	0° C to +75° C	93S10XC	93S16XC
Hermetic DIP	-55° C to +125° C	93S10DM	93S16DM
Hermetic Flat Pak	-55° C to +125° C	93S10FM	93S16FM
Dice	-55° C to +125° C	93S10XM	93S16XM

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

Am93S10 • Am93S16

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am93S10XC, Am93S16XC
Am93S10XM, Am93S16XM

T_A = 0°C to 75°C
T_A = -55°C to +125°C

V_{CC} = 5.0V ±5% (COM'L)
V_{CC} = 5.0V ±10% (MIL)

MIN. = 4.75V
MIN. = 4.5V

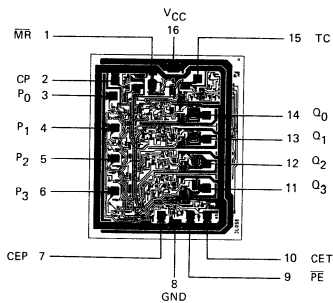
MAX. = 5.25V
MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1mA V _{IN} = V _{IH} or V _{IL}	XM	2.5	3.4	Volts
			XC	2.7	3.4	
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}		0.35	0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{IL} (Note 3)	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V	P; MR; CEP		-2.0	mA
			CET		-3.0	
			PE		-4.0	
			CP		-5.0	
I _{IH} (Note 3)	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V	P; MR; CEP		50	μA
			CET		75	
			PE		100	
			CP		125	
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX.	-40	-65	-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)		82	127	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
5. Outputs open; MR = 0V; all other inputs HIGH.

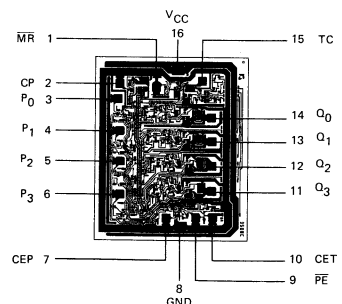
Metallization and Pad Layouts

Am93S10



DIE SIZE 0.078" X 0.096"

Am93S16



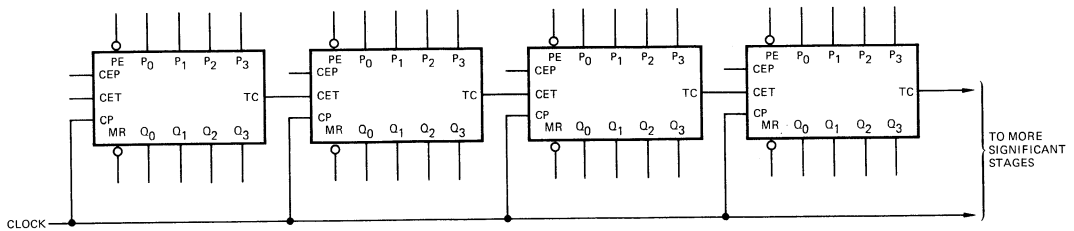
DIE SIZE 0.078" X 0.096"

SWITCHING CHARACTERISTICS ($T_A = +25^\circ$)

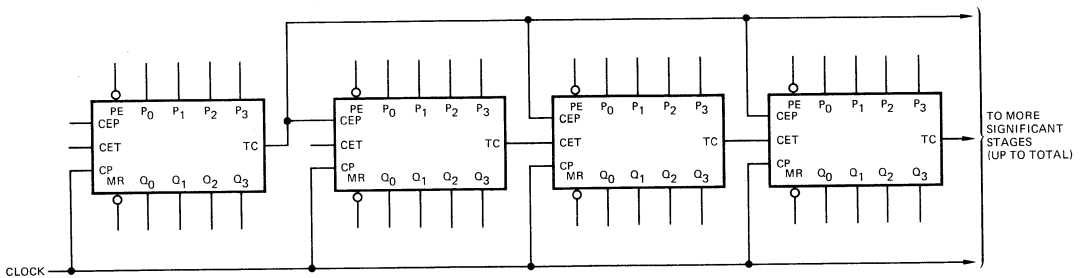
Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
f _{MAX}	Count Frequency	V _{CC} = 5.0V, C _L = 15 pF, R _L = 280Ω	70	100		MHz
t _{PLH}	Clock to Q		6	9		ns
t _{PHL}			8.5	13		
t _{PLH}	Clock to TC		12	18		ns
t _{PHL}			8	12		
t _{PLH}	CET to TC		6.5	10		ns
t _{PHL}			6.5	10		
t _{PHL}	MR to Q		14	20		ns
t _s	Recovery Time for MR (inactive)		6			ns
t _{pw}	Master Reset Pulse Width		13			ns
t _{pw}	Clock Pulse Width HIGH		6			ns
	Clock Pulse Width LOW		10			
t _s	Data to Clock		8			ns
t _h			0			
t _s	PE to Clock	16			ns	
t _h		0				
t _s	CEP or CET to Clock	12			ns	
t _h		0				

APPLICATIONS

SYNCHRONOUS MULTISTAGE COUNTING USING CET INPUT ONLY



FASTER SYNCHRONOUS MULTISTAGE COUNTING USING CET AND CEP INPUTS



DEFINITION OF FUNCTIONAL TERMS

PE Parallel Enable. When \overline{PE} is LOW, the parallel inputs, P₀ through P₃, are enabled. When \overline{PE} is HIGH, the count function is possible.

CEP Count Enable Parallel. CEP is one of the count enable inputs that must be HIGH for the counter to count.

CET Count Enable Trickle. CET is one of the count enable inputs that must be HIGH for the counter to count. In addition, CET is included in the TC output gate and must be HIGH for TC to be HIGH.

CP Clock Pulse. Causes the required output change on the LOW-to-HIGH transition (Edge-triggered).

MR Master Reset. When the asynchronous master reset is LOW, the Q₀ through Q₃ outputs will be LOW regardless of the other inputs.

P₀, P₁, P₂, P₃ The parallel data inputs for the four internal flip-flops.

Q₀, Q₁, Q₂, Q₃ The four parallel outputs from the counter.

TC Terminal Count. The terminal count output will be HIGH for CET HIGH and binary nine on the Am93S10 or CET HIGH and binary 15 on the Am93S16.

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
\overline{MR}	1	1	—	—
CP	2	2.5	—	—
P ₀	3	1	—	—
P ₁	4	1	—	—
P ₂	5	1	—	—
P ₃	6	1	—	—
CEP	7	1	—	—
GND	8	—	—	—
\overline{PE}	9	2	—	—
CET	10	1.5	—	—
Q ₃	11	—	20	10
Q ₂	12	—	20	10
Q ₁	13	—	20	10
Q ₀	14	—	20	10
TC	15	—	20	10
V _{CC}	16	—	—	—

A Schottky TTL Unit Load is defined as 50μA measured at 2.7V HIGH and -2.0mA measured at 0.5V LOW.

FUNCTION TABLE

INPUTS									OUTPUTS			
CP	\overline{MR}	\overline{PE}	CEP	CET	P ₀	P ₁	P ₂	P ₃	Q ₀	Q ₁	Q ₂	Q ₃
X	L	X	X	X	X	X	X	X	L	L	L	L
↑	H	L	X	X	D ₀	D ₁	D ₂	D ₃	D ₀	D ₁	D ₂	D ₃
↑	H	H	L	L	X	X	X	X	NC	NC	NC	NC
↑	H	H	L	H	X	X	X	X	NC	NC	NC	NC
↑	H	H	H	L	X	X	X	X	NC	NC	NC	NC
↑	H	H	H	H	X	X	X	X	COUNT			

H = HIGH
L = LOW
X = Don't Care

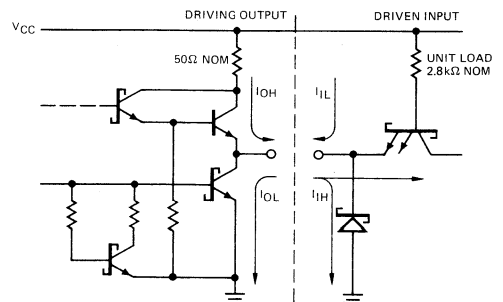
NC = No Change
D_i may be either HIGH or LOW
↑ LOW-to-HIGH Transition

TERMINAL COUNT (TC) TRUTH TABLE

Am93S10					Am93S16					TC
CET	Q ₀	Q ₁	Q ₂	Q ₃	CET	Q ₀	Q ₁	Q ₂	Q ₃	
H	H	L	L	H	H	H	H	H	H	H
L	X	X	X	X	L	X	X	X	X	L
X	L	X	X	X	X	L	X	X	X	L
X	X	H	X	X	X	X	L	X	X	L
X	X	X	H	X	X	X	X	L	X	L
X	X	X	X	L	X	X	X	X	L	L

H = HIGH
L = LOW
X = Don't Care

SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.

Am93S48

Twelve-Input Parity Checker/Generator

Distinctive Characteristics

- Generates or checks parity over 12 bits
- Advanced Schottky technology

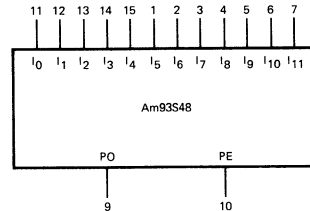
- Same delay to EVEN and ODD parity outputs
- 100% reliability assurance testing in compliance with MIL-STD-883.

FUNCTIONAL DESCRIPTION

The Am93S48 is a high-speed, 12-input parity checker or parity generator. The device is built using advanced Schottky technology and also incorporates PNP input transistors to reduce the input loading to only 0.4 STTL Unit Loads.

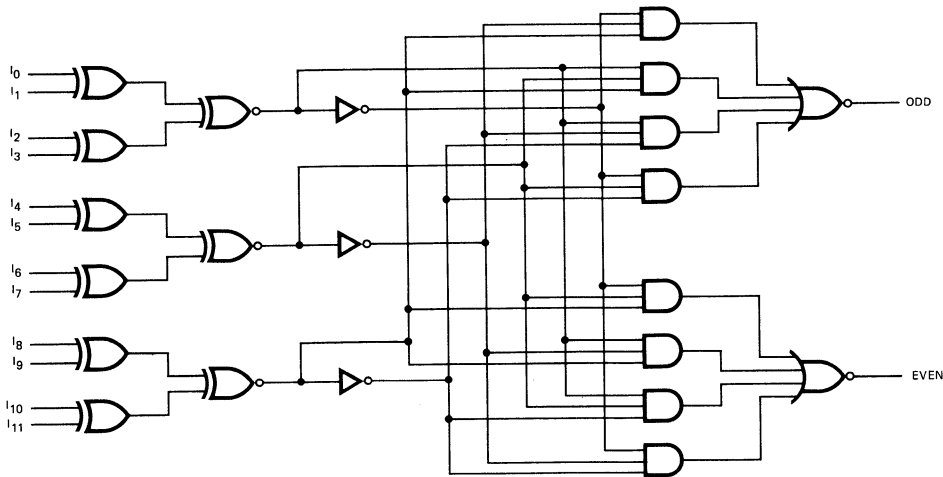
Both an ODD parity output and an EVEN parity output are obtained with the same propagation delay. This is accomplished by using an output structure that looks at the input as three 4-bit parity trees.

LOGIC SYMBOL



V_{CC} = Pin 16
GND = Pin 8

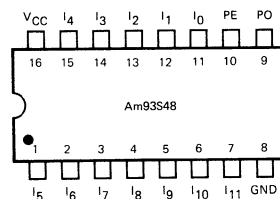
LOGIC DIAGRAM



ORDERING INFORMATION

Package Type	Temperature Range	Order Number
Molded DIP	0°C to +70°C	93S48PC
Hermetic DIP	0°C to +70°C	93S48DC
Dice	0°C to +70°C	93S48XC
Hermetic DIP	-55°C to +125°C	93S48DM
Hermetic Flat Pak	-55°C to +125°C	93S48FM
Dice	-55°C to +125°C	93S48XM

CONNECTION DIAGRAM Top View



Note: Pin 1 is marked for orientation.

4

Am93S48

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5V to +7V
DC Voltage Applied to Outputs for HIGH Output State	-0.5V to +V _{CC} max.
DC Input Voltage	-0.5V to +5.5V
DC Output Current, Into Outputs	30mA
DC Input Current	-30mA to +5.0mA

ELECTRICAL CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (Unless Otherwise Noted)

Am93S48XC	T _A = 0°C to +70°C	V _{CC} = 5.0V ±5% (COM'L)	MIN. = 4.75V	MAX. = 5.25V
Am93S48XM	T _A = -55°C to +125°C	V _{CC} = 5.0V ±10% (MIL)	MIN. = 4.5V	MAX. = 5.5V

Parameters	Description	Test Conditions (Note 1)	Min.	Typ. (Note 2)	Max.	Units
V _{OH}	Output HIGH Voltage	V _{CC} = MIN., I _{OH} = -1mA	XC	2.7		Volts
		V _{IN} = V _{IH} or V _{IL}	XM	2.5		
V _{OL}	Output LOW Voltage	V _{CC} = MIN., I _{OL} = 20mA V _{IN} = V _{IH} or V _{IL}			0.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs	2.0			Volts
V _{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	Volts
V _I	Input Clamp Voltage	V _{CC} = MIN., I _{IN} = -18mA			-1.2	Volts
I _{IL} (Note 3)	Input LOW Current	V _{CC} = MAX., V _{IN} = 0.5V			-0.8	mA
I _{IH} (Note 3)	Input HIGH Current	V _{CC} = MAX., V _{IN} = 2.7V			20	μA
I _I	Input HIGH Current	V _{CC} = MAX., V _{IN} = 5.5V			1.0	mA
I _{SC}	Output Short Circuit Current (Note 4)	V _{CC} = MAX., V _{OUT} = 0.0V	-40		-100	mA
I _{CC}	Power Supply Current	V _{CC} = MAX. (Note 5)		57	80	mA

- Notes: 1. For conditions shown as MIN. or MAX., use the appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
 3. Actual input currents = Unit Load Current x Input Load Factor (See Loading Rules).
 4. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
 5. Both outputs open; all inputs at 4.5V.

Switching Characteristics (T_A = +25°C)

Parameters	Description	Test Conditions	Min.	Typ.	Max.	Units
t _{PLH}	I _O through I ₁₁ to	V _{CC} = 5.0V, C _L = 15 pF, R _L = 280Ω		19	28	ns
t _{PHL}	Even Output			19	28	ns
t _{PLH}	I _O through I ₁₁ to			19	28	ns
t _{PHL}	Odd Output			19	28	ns

TRUTH TABLE

NUMBER OF I INPUTS		OUTPUT	
LOW	HIGH	ODD	EVEN
0	12	L	H
1	11	H	L
2	10	L	H
3	9	H	L
4	8	L	H
5	7	H	L
6	6	L	H
7	5	H	L
8	4	L	H
9	3	H	L
10	2	L	H
11	1	H	L
12	0	L	H

H = HIGH
L = LOW
X = Don't Care

LOADING RULES (In Unit Loads)

Input/Output	Pin No.'s	Input Unit Load	Fan-out	
			Output HIGH	Output LOW
I ₅	1	0.4	—	—
I ₆	2	0.4	—	—
I ₇	3	0.4	—	—
I ₈	4	0.4	—	—
I ₉	5	0.4	—	—
I ₁₀	6	0.4	—	—
I ₁₁	7	0.4	—	—
GND	8	—	—	—
PO	9	—	20	10
PE	10	—	20	10
I ₀	11	0.4	—	—
I ₁	12	0.4	—	—
I ₂	13	0.4	—	—
I ₃	14	0.4	—	—
I ₄	15	0.4	—	—
V _{CC}	16	—	—	—

A Schottky TTL Unit Load is defined as 50μA measured at 2.7V HIGH and -2.0mA measured at 0.5V LOW.

DEFINITION OF FUNCTIONAL TERMS

I₀ through I₁₁ The twelve inputs to the parity tree.

ODD The ODD parity output of the device. When an ODD number of I inputs are at a HIGH level, the ODD output will be HIGH.

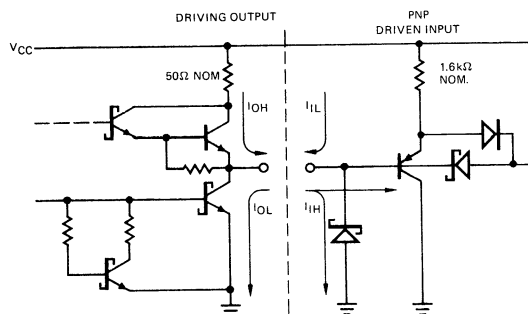
EVEN The EVEN parity output of the device. When an EVEN number of I inputs are at a HIGH level, the EVEN output will be HIGH.

LOGIC EQUATIONS

$$\text{Odd Output} = I_0 \oplus I_1 \oplus I_2 \oplus I_3 \oplus I_4 \oplus I_5 \oplus I_6 \oplus I_7 \oplus I_8 \oplus I_9 \oplus I_{10} \oplus I_{11}$$

$$\text{Even Output} = \overline{I_0 \oplus I_1 \oplus I_2 \oplus I_3 \oplus I_4 \oplus I_5 \oplus I_6 \oplus I_7 \oplus I_8 \oplus I_9 \oplus I_{10} \oplus I_{11}}$$

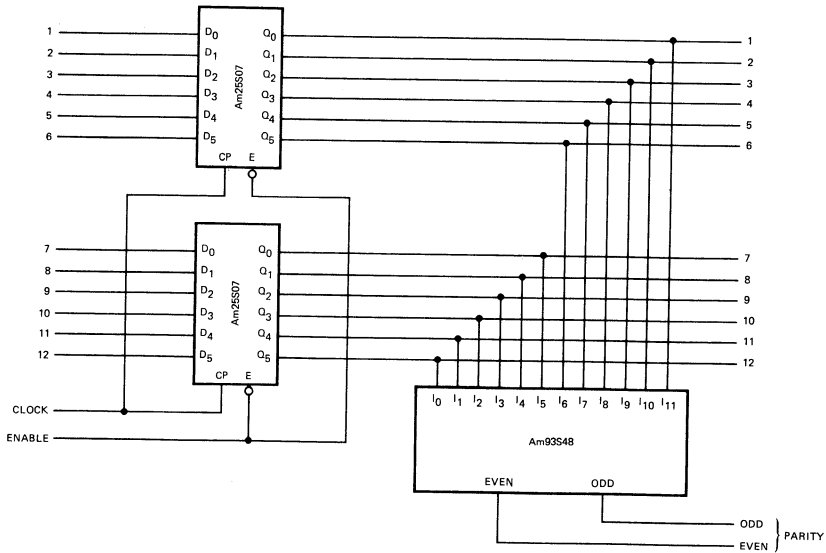
SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



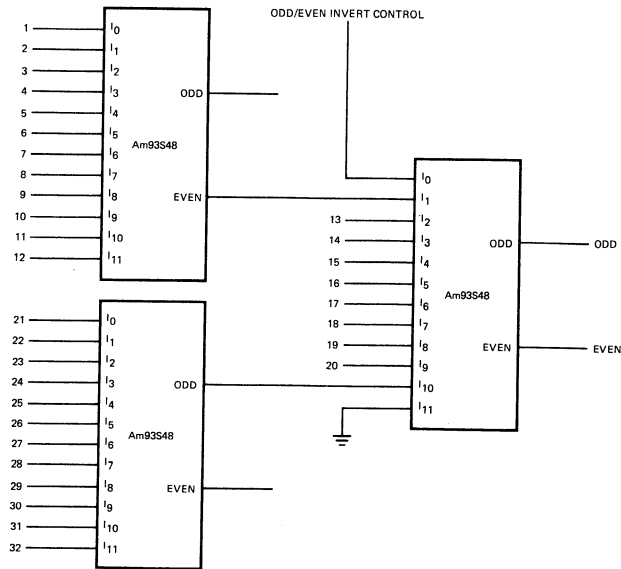
Note: Actual current flow direction shown.

APPLICATIONS

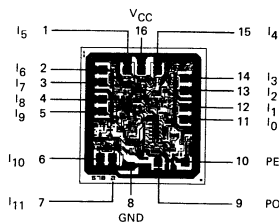
12-BIT PARALLEL ODD/EVEN PARITY CHECKER/GENERATOR



32-BIT PARITY CHECKER/GENERATOR



Metallization and Pad Layout



DIE SIZE 0.067" X 0.072"

Digital Signal Processing Handbook

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INTRODUCTION

The significant cost reductions which have been achieved with digital integrated circuits in recent years have allowed digital processing techniques to be applied in many new fields. One of the most important of these is digital signal processing.

Digital arithmetic processors are now used to perform frequency analysis, correlation and filtering functions which, at one time, were the exclusive province of analog systems. Digital signal processors have several obvious advantages over analog approaches. These include precision and programmability as well as insensitivity to temperature, power supply variations, and component aging.

Digital signal processors are similar to general-purpose digital computers except for the need to perform large numbers of multiplications. The first digital signal processors frequently used general-purpose adders programmed to do the multiplication. More recently, integrated circuits such as the Advanced Micro Devices' Am2505 two's complement multiplier were introduced specifically for this function. The Am2505 was quickly accepted as the industry standard device for military applications. It was soon followed by high-speed, Am2505, and low-power, Am25L05, versions. Although these devices significantly reduced the cost and improved the performance of signal processors used for digital filters and Fast Fourier Transform analyzers, digital techniques were still only economically viable for very sophisticated applications.

The development of low-power Schottky technology, which provides the same performance as standard TTL at up to one-fifth the power dissipation, now permits the design of low-cost MSI and LSI devices suitable for use in general commercial digital signal processing systems. Advanced Micro Devices has recently introduced a number of products designed specifically for these applications. They include the Am25LS14 Serial/Parallel Multiplier, Am25LS15 Quad Adder/Subtractor and the Am25LS22 8-Bit Serial/Parallel Register.

This handbook offers a general introduction to digital signal processing techniques. Particular emphasis has been given to the application of low-power Schottky integrated circuits in the design of digital filters.

We hope that this information will aid engineers in implementing digital signal processing methods in cost conscious commercial systems. Typical applications include process control, data compression, data transmission, spectrum analyzers, medical electronics and special purpose instrumentation as well as hardware multiplication and division in high-speed minicomputer designs.

BASIC DIGITAL FILTER THEORY

By John R. Mick

INTRODUCTION

Digital filtering applications are rapidly expanding as new developments in technology provide increased packing density in complex integrated circuits. Until recently digital filter processing algorithms have been used primarily in computer simulations, sampled data analysis and data reduction computations. The variety of complex integrated circuits suitable in size, weight, power and cost for real-time processing of video signals by digital techniques is increasing steadily. With the increasingly extensive application of digital processors to many systems, more and more importance is placed on the development of mathematical tools for the analysis and design of sampled data systems. In particular the classical methods of difference equation solutions are available to the designer as well as the "z-transform" calculus solutions. The latter analytical method results in considerable simplification and understanding of the problems associated with sampled-data systems.

This application note presents a brief review of these concepts. A brief introduction to sampling theory is presented and a review of the difference equation as applicable to digital filtering follows. Several digital filter configurations are outlined and a summary of the most useful transforms for designing digital filters is also presented.

Definition

The term "digital filter" refers to a computational algorithm performed on a sampled input signal resulting in a transformed output signal. The input signal is a sequence of numbers from either an analog-to-digital converter or a direct digital input source. The computational process can correspond to high-pass filtering, low-pass filtering, band-pass filtering, integration, differentiation etc. The output signal is either a direct digital sequence or a regenerated analog signal from a digital-to-analog converter.

Advantages

Several unique advantages are offered by the digital approach to signal processing. These include:

1. Performance from unit to unit is stable and repeatable.
2. Arbitrarily high precision is achieved that is limited only by the number of bits carried in memory and by the input and output resolution capabilities.
3. No impedance matching problems exist in the digital domain.
4. Critical filter break frequencies can be placed without restriction (influences the precision required).
5. Component value variation problems normally associated with capacitors and resistors due to temperature changes or age are nonexistent.
6. Greater flexibility is achieved since filter response can be changed by varying the proper arithmetic coefficients.
7. The intrinsic possibility of time-sharing major implementation sections exists (adders, subtractors, multipliers etc).

8. Small size results from integrated circuit implementation.
9. Periodic calibration as is required with analog circuits is eliminated.
10. Performance limitations of physical analog components are avoided.

THE SAMPLING PROCESS

It's convenient to think of the sampling process as an impulse modulation of a continuous input signal. Accordingly if the input signal $v(t)$ is sampled every T seconds, an output signal results denoted $v^*(t)$. This is shown in Figure 1.

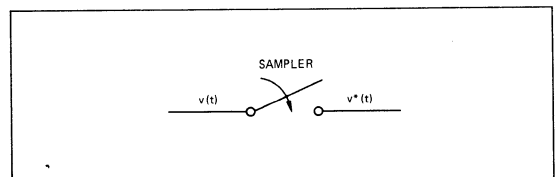


Figure 1. Sampler Representation.

The ideal sampler is represented by using the Dirac delta function to express a unit impulse train $\delta(t-nT)$. This notation represents impulses occurring at each $t = nT$ seconds for n equal to positive integers. The ideal sampler $\delta_T(t)$ for a continuous train of regularly spaced pulses is described for positive time sequences by the following equation:

$$\delta_T(t) = \sum_{n=0}^{\infty} \delta(t-nT) \quad (1)$$

The sampler output signal is written in terms of a continuous input signal and the ideal sampler unit impulse train as

$$v^*(t) = v(t) \sum_{n=0}^{\infty} \delta(t-nT) \quad (2)$$

This equation is rewritten to include the input signal as a time function when $t = nT$ as

$$v^*(t) = \sum_{n=0}^{\infty} v(nT) \delta(t-nT) \quad (3)$$

This equation shows that the sampler output is an impulse train with an amplitude equal to the continuous input signal amplitude at the sampling instant.

The Laplace transform of the ideal sampler is the Laplace transform of the Dirac impulse train $\delta_T(t)$ and is given by

$$\mathcal{L}[\delta_T(t)] = \mathcal{L}\left[\sum_{n=0}^{\infty} \delta(t-nT)\right] = \sum_{n=0}^{\infty} e^{-nTs} \quad (4)$$

Basic Digital Filter Theory

since the Laplace transform of the unit impulse function $\delta(t-nT)$ is e^{-nTs} ,

Using equation 4, the Laplace transform of equation 3, the sampler output becomes

$$V^*(s) = \sum_{n=0}^{\infty} v(nT)e^{-nTs} \quad (5)$$

This is very similar to the definition of the continuous Laplace transform

$$V(s) = \int_0^{\infty} v(t)e^{-st} dt \quad (6)$$

except that the integral is replaced by a summation evaluated at the sampling instants $t = nT$ of the unit impulse train.

Time Domain Sampling

The time domain analysis of the above described sampler is best understood by considering a continuous sinusoidal input signal

$$v(t) = A \sin(\omega t) \quad (7)$$

Using equation 3, the sampler output for the sinusoidal input is

$$V^*(t) = \sum_{n=0}^{\infty} A \sin(\omega nT) \delta(t-nT) \quad (8)$$

Figure 2 shows the time domain response of a sinusoidal input signal, a sampler, and a sampler output as described by the above equations, where the sampling rate is considerably higher than the continuous input frequency.

Using equation 5, the Laplace transform of equation 8 describing the sampler output for the sinusoidal input is

$$V^*(s) = \sum_{n=0}^{\infty} A \sin(\omega nT) e^{-nTs} \quad (9)$$

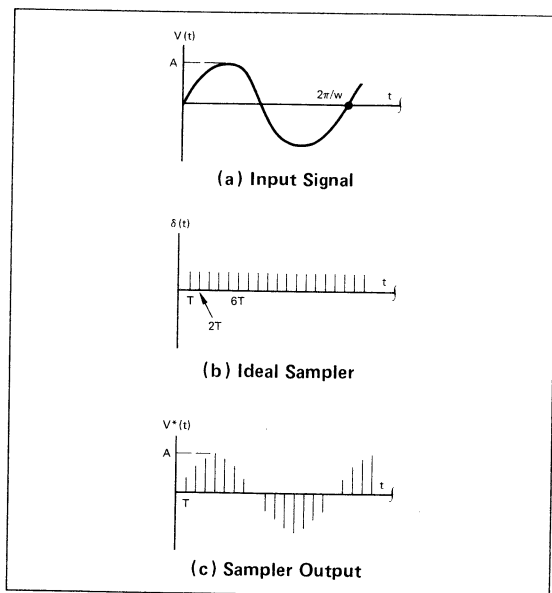


Figure 2. Time Domain Sampling.

The time domain analysis gives a useful picture of the sampler characteristics as a function of time; however, the complete picture also requires an analysis of the sampler in the frequency domain.

Frequency Domain Sampling

To examine the characteristics of the ideal sampler in the frequency domain, the Laplace transform of the ideal sampler as established in equation 4 is expanded as

$$\sum_{n=0}^{\infty} e^{-nTs} = 1 + e^{-sT} + e^{-2sT} + e^{-3sT} + \dots \quad (10)$$

The closed form of this geometric series is

$$\sum_{n=0}^{\infty} e^{-nTs} = \frac{1}{1 - e^{-sT}} \quad (11)$$

Thus the Laplace transform of the sampler output is given by the convolution of the ideal sampler and the continuous input signal as

$$V^*(s) = V(s) * \left[\frac{1}{1 - e^{-sT}} \right] \quad (12)$$

Since convolution in the s-domain requires contour integration²¹, only the result is stated; the sampler output for a continuous input is

$$V^*(s) = \frac{1}{T} \sum_{n=-\infty}^{\infty} V(s + jn\omega_s) \quad (13)$$

It is important to note that the sampler and its output are periodic with period $j\omega_s$. This means $V^*(s)$ is equal to $V^*(s + j\omega_s)$ and is represented in the s-plane by periodic strips along the $j\omega$ axis. As a result, the sampler causes a periodic single line spectrum in the frequency domain occurring at each integer multiple of the sampling frequency.

Assuming a continuous sinusoidal input signal

$$v(t) = A \sin(\omega_a t) \quad (14)$$

and a sampler operating at radian frequency ω_s , the output spectrum is periodic with spurious sidebands located at all multiples of ω_s . The input spectrum is centered around each of these spurious multiples of the sampling frequency. This is shown in Figure 3.

The Z-Transform

The z-transform is used to describe a sampled data system in much the same way as the Laplace transform is used to describe a continuous time system. The z-transform of a signal describes the signal at the sampling instant and therefore contains information about the corresponding time function at the sampling instants only. The z-transform is obtained by making the substitution

$$z = e^{sT} \quad (15)$$

or

$$s = \frac{1}{T} \ln(z) \quad (16)$$

where z is interpreted as a complex Laplace variable. Thus, every continuous signal that has a Laplace transform also has a z-transform by a simple substitution.

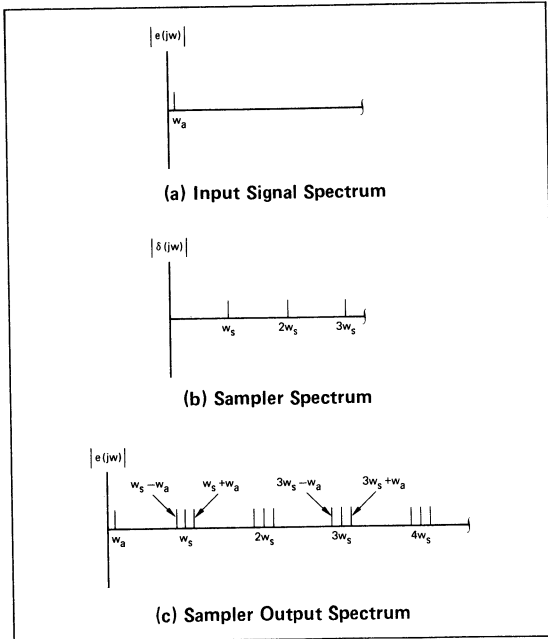


Figure 3. Frequency Domain Sampling.

Since the Laplace transform of a sampler is periodic, the z-transform performs a change of variable which retains the s-plane pole-zero configuration while stripping the function of its repetitive character. Thus, the z-transform allows simple algebraic manipulation of the polynomials in the z-plane just as the Laplace transform does for the polynomials in the s-plane.

The above substitution maps the periodic strip from $-w_s/2$ to $+w_s/2$ of the jw -axis of the s-plane onto the unit circle of the z-plane where w_s is the sampling frequency. The remainder of this strip in the left-hand, s-plane is mapped inside the unit circle in the z-plane. This is shown in Figure 4.

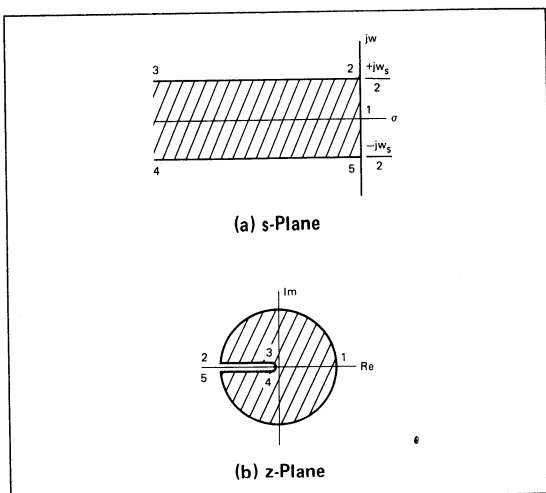


Figure 4. S-Plane to z-Plane Transformation.

Successive $w_s = 2\pi/T$ strips of the left hand side of the s-plane are mapped into the same unit circle of the z-plane. Likewise, the corresponding right-half strip is mapped as the exterior of the unit circle in the z-plane. If a transfer function is to be stable, its poles are in the left half of the s-plane; thus, the poles of the transformed function must lie within the unit circle in the z-plane. It follows that the z-plane poles and zeros occur on the real axis or in complex conjugate pairs.

The interval from $-w_s/2$ to $+w_s/2$ is known as the Nyquist interval. This interval places a bound on the bandwidth of the input signal to the sampler such that if the input signal is not bandlimited to below the radian frequency $w_s/2$, it cannot be recovered exactly at the output. Figure 5a shows the aliasing problems on the input spectrum after sampling if the input signal is not bandlimited while Figure 5b shows the spectrum of a bandlimited signal before and after sampling.

Using the substitution $z = e^{sT}$ on equation 3, the z-transform output for a sampled input signal is found as

$$V^*(z) = \sum_{n=0}^{\infty} v(nT)z^{-n} \tag{17}$$

where z^{-n} is a delay operator and n is an integer representing the number of past unit delays.

THE DIFFERENCE EQUATION

In linear continuous (analog) filter theory, linear differential equations is one mathematical tool available to describe the transfer function. Similarly, in linear digital (sampled) filter theory, the linear difference equation is available as a mathematical tool for analysis and synthesis.

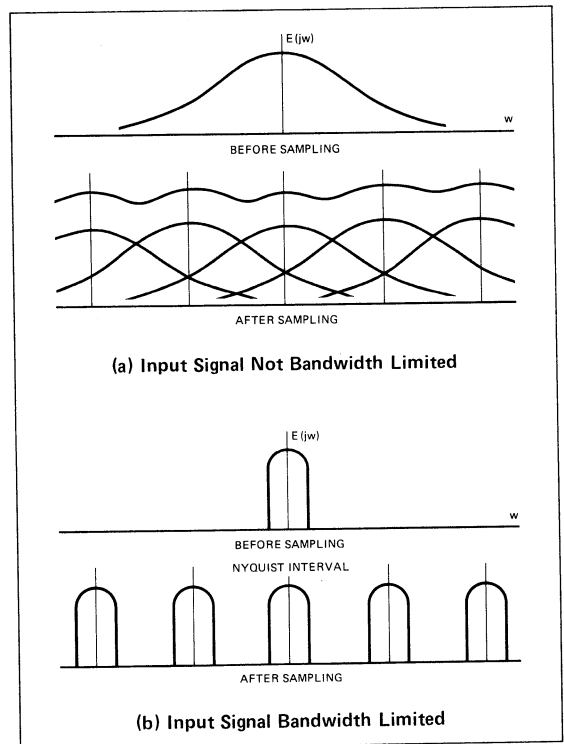


Figure 5. Effect of Bandlimiting Before Sampling.

Basic Digital Filter Theory

The linear difference equation is used to define the sampled output pulse amplitude $y(t)$ as a function of the present input pulse and any number of past input and output pulses. A general form of the difference equation¹³ is

$$y(nT) = \sum_{i=0}^N A_i x(nT-iT) + \sum_{i=1}^M B_i y(nT-iT) \quad (18)$$

where the notation $x(nT)$ represents the present input sample and the $x(iT)$ are past input samples. Similarly, $y(nT)$ is the present output sample and the $y(iT)$ are past output samples. The A_i and B_i coefficients are a set of constants which determine the response of the filter.

The z-transform of the general difference equation 18 is derived by using equation 17 and is given as

$$y(z) = x(z) \sum_{i=0}^N A_i z^{-i} + y(z) \sum_{i=1}^M B_i z^{-i} \quad (19)$$

This equation is interpreted as: the present output is equal to the present and past inputs each multiplied by the respective coefficient A_i plus the past outputs each multiplied by the respective coefficient B_i . Equation 19 is rewritten in the normal transfer function form as

$$H(z) = \frac{y(z)}{x(z)} = \frac{\sum_{i=0}^N A_i z^{-i}}{1 - \sum_{i=1}^M B_i z^{-i}} \quad (20)$$

This is the general form of a transfer function in the z-plane that can be made equal to a transfer function in the s-plane to realize the sampled equivalent of a linear continuous filter.

First Order Equation

A first order difference equation is written as

$$y(nT) = A_0 x(nT) + A_1 x(nT-T) + B_1 y(nT-T) \quad (21)$$

The z-transform of this difference equation is

$$E_o(z) = A_0 E_i(z) + A_1 z^{-1} E_i(z) + B_1 z^{-1} E_o(z) \quad (22)$$

where E_o is used to represent the output signal and E_i is used to represent the input signal. The transfer function is obtained by rewriting this equation as

$$\frac{E_o(z)}{E_i(z)} = H(z) = \frac{A_0 + A_1 z^{-1}}{1 - B_1 z^{-1}} = \frac{A_0 z + A_1}{z - B_1} \quad (23)$$

This transfer function can be implemented as shown in Figure 6.

Second Order Equation

A second order difference equation is written as

$$y(nT) = A_0 x(nT) + A_1 x(nT-T) + A_2 x(nT-2T) + B_1 y(nT-T) + B_2 y(nT-2T)$$

The z-transform of this difference equation is

$$E_o(z) = A_0 E_i(z) + A_1 z^{-1} E_i(z) + A_2 z^{-2} E_i(z) + B_1 z^{-1} E_o(z) + B_2 z^{-2} E_o(z) \quad (25)$$

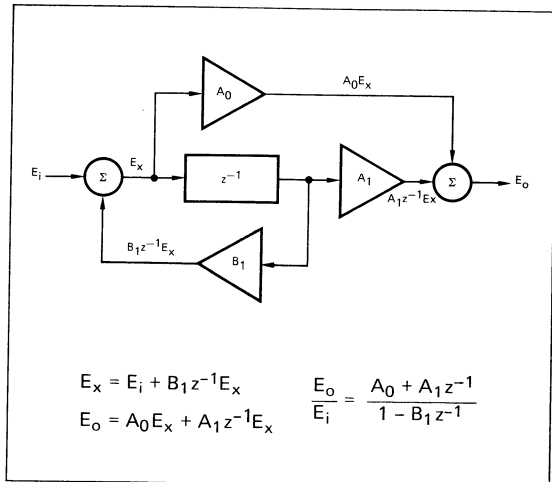


Figure 6. Implementation of First Order Difference Equation.

The transfer function is obtained by rewriting this equation as

$$\frac{E_o(z)}{E_i(z)} = H(z) = \frac{A_0 + A_1 z^{-1} + A_2 z^{-2}}{1 - B_1 z^{-1} - B_2 z^{-2}} = \frac{A_0 z^2 + A_1 z + A_2}{z^2 - B_1 z - B_2} \quad (26)$$

This transfer function can be implemented as shown in Figure 7.

Difference Equation Summary

The first and second order difference equations, their z-transform functions, and their circuit implementations serve as illustrative examples of the equivalence of the mathematical description and the hardware associated with digital filters. Since the z-transform is equal to the Laplace transform by means of the substitution $z = e^{sT}$, the first and second order implementations are mathematically related to s-plane transfer functions. A great wealth of information for design and synthesis of analog filters using Laplace transforms is available in the literature. It is therefore possible to use these procedures to design an equivalent analog transfer function, then transform this function to the z-plane and implement an equivalent digital filter using an appropriate configuration.

DIGITAL FILTER CONFIGURATIONS

If the output $y(nT)$ of a digital filter is a function of the present and past input samples, the filter is termed non-recursive. That is, all B_i of the general difference equation and zero. (Reference equation 27). If the past output samples are included in the algorithm, then the digital filter is termed recursive.

Canonical Forms

There are three canonical forms of realizing a general recursive digital filter. These are the direct form, the cascade form and the parallel form.

In the direct form the output sequence is calculated by implementing the difference equation directly. Since the general equation is

$$y(nT) = \sum_{i=0}^N A_i x(nT-iT) + \sum_{i=1}^M B_i y(nT-iT) \quad (27)$$

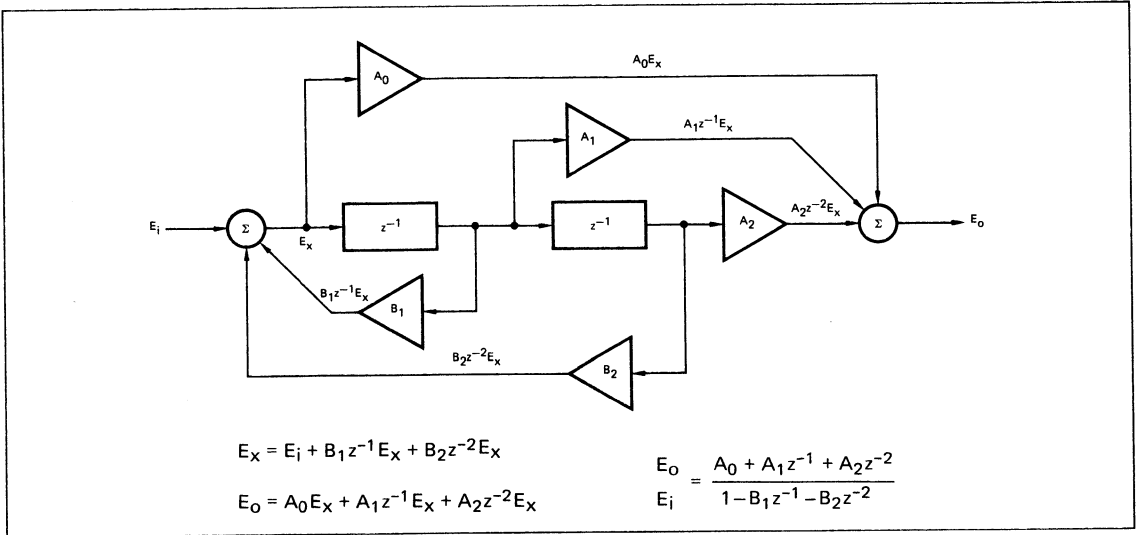


Figure 7. Implementation of Second Order Difference Equation.

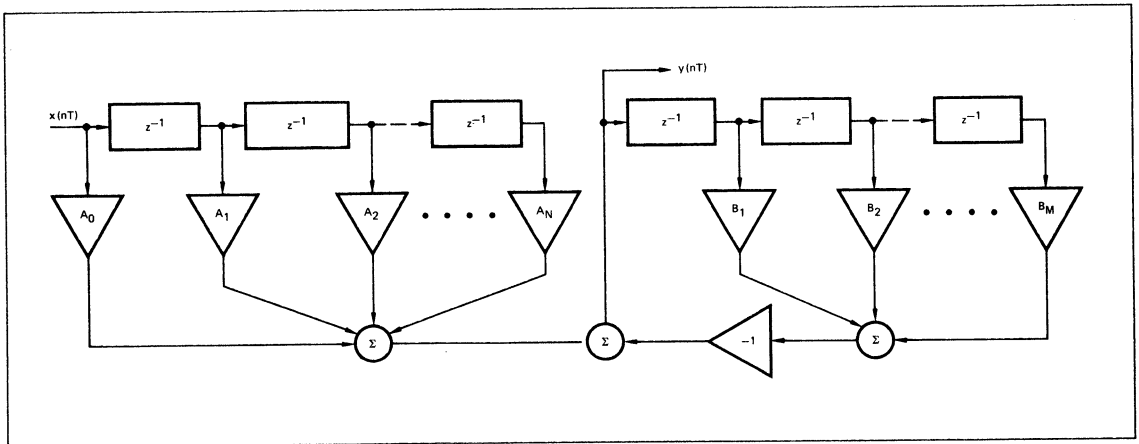


Figure 8. Direct Canonical Form.

the direct form digital filter takes the configuration of Figure 8. Figure 9 depicts another configuration of the direct canonic form in which the memory elements (z^{-1}) are shared by the feedback and feedforward loops. This direct form suffers from the fact that the pole locations are extremely sensitive functions of the coefficients B_i for higher order filters⁷. This directly affects the precision required for the entire digital filter.

In the cascade form the digital filter is implemented from the transfer function written as a product of factors.

$$H(z) = A \frac{K_1 \prod_{i=1}^N (1 + a_i z^{-1} + b_i z^{-2})}{K_2 \prod_{i=1}^M (1 + c_i z^{-1} + d_i z^{-2})} \quad (28)$$

This configuration consists of a series of lower order filters connected in cascade as shown in Figure 10. The pole coefficients c_i and d_i are not nearly as sensitive as the direct form⁴. Therefore, this form is especially practical for higher order filters.

The parallel canonical form is implemented by writing the transfer function as a sum of partial fractions.

$$H(z) = A_0 + \sum_{i=1}^K \left[B_i \frac{a_i + b_i z^{-1}}{1 + c_i z^{-1} + d_i z^{-2}} \right] \quad (29)$$

This configuration consists of a group of lower order filters each operating on the input signal with the output of the parallel bank of filters summed together as in Figure 11.

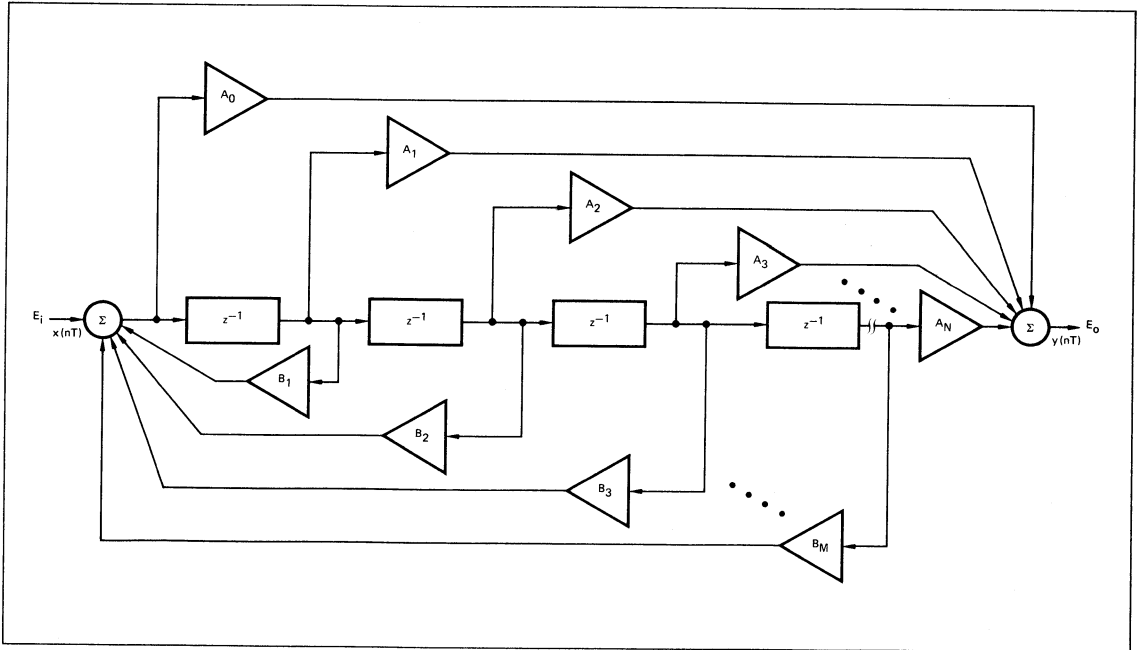


Figure 9. Direct Canonical Form With Feedback and Feedforward Loops Sharing the Same Memory.

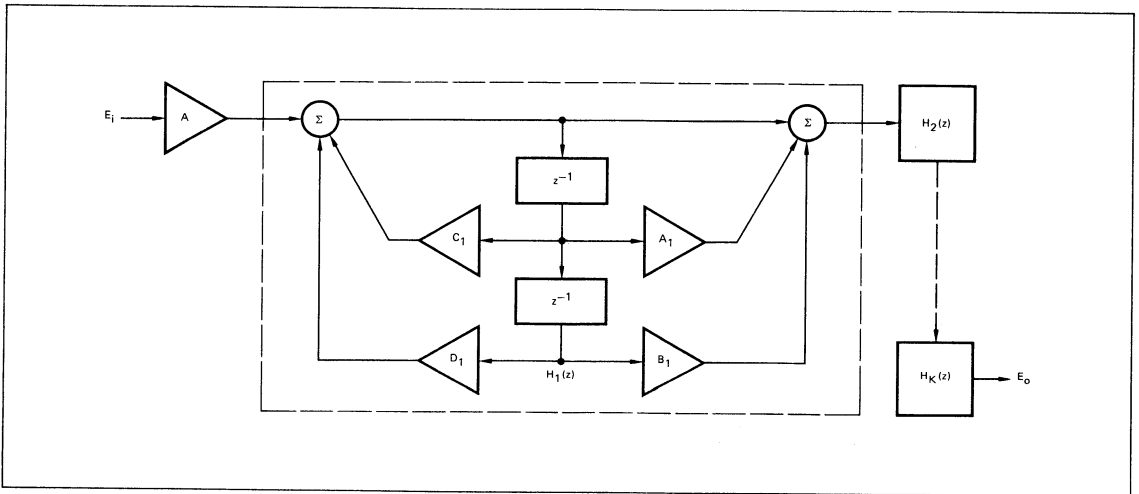


Figure 10. Cascade Canonical Form.

Other Configurations

Figure 12 illustrates a recursive one-pole, one-zero building block while Figure 13 represents a recursive two-pole, two-zero building block. In these structures, the B_i determine the pole locations in the z-plane while the A_i determine the zero locations in the z-plane.

A general recursive two-pole building block with the z-plane transfer function is shown in Figure 14.

It is apparent that many digital filter configurations can be

designed. Each configuration has properties that may or may not be desirable depending on the particular application. Thus, each application must be treated individually and it is difficult to generalize that one configuration is always superior.

SYNTHESIS TECHNIQUES

There are three transform techniques that find the greatest application in the design of digital filters from continuous transfer functions. These are the standard z-transform, the bilinear z-transform and the matched z-transform.

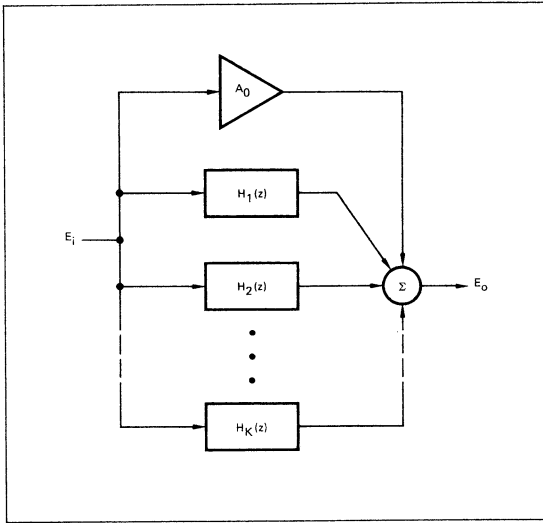


Figure 11. Parallel Canonical Form.

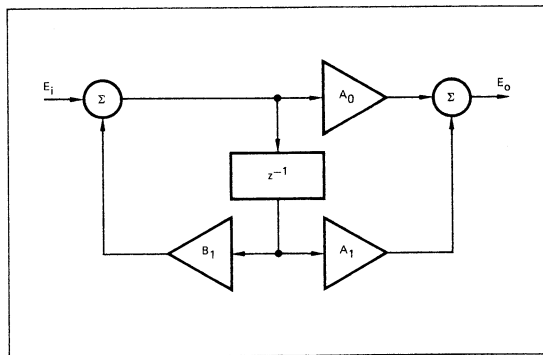


Figure 12. Recursive One-Pole Structure.

Standard Z-Transform Method

The standard z-transform, also known as the impulse invariant technique, utilizes the partial fraction expansion of the continuous filter transfer function. This transformation preserves the impulse response of the sampled continuous filter and is best suited for low-pass and band-pass applications.

In using this technique the Laplace transform partial fraction expansion terms are replaced by the appropriate z-transform terms. The substitutions used are shown in Table 1.

From this it is seen that the standard z-transform technique gives a transfer function of the form

$$H(z) = A_0 + \sum_{i=1}^K \frac{a_i}{1 - b_i z^{-1}} + \sum_{j=1}^L \frac{a_j + b_j z^{-1}}{1 + c_j z^{-1} + d_j z^{-2}} \quad (30)$$

where any of the above coefficients may be zero.

Thus, the coefficients are defined uniquely and the digital filter can be implemented directly using one-pole and two-pole building blocks in the parallel canonical form as described in the previous section.

Bilinear Transformation Method

The bilinear z-transform is an algebraic mapping transformation utilizing the substitution

$$s = \frac{2(1 - z^{-1})}{T(1 + z^{-1})} \quad (31)$$

This transform maps a sampling interval from $-j\omega_s/2$ to $+j\omega_s/2$ in the s-plane onto the unit circle in the z-plane. It should be noted however, that this transform does not yield a linear map as does the substitution $z = e^{st}$; that is, a non-linear warping of the frequency scale in the z-plane results. The magnitude of this warping is given by

$$W_A = \frac{2}{T} \tan\left(\frac{\omega_D T}{2}\right) \quad (32)$$

where ω_A = s-plane frequency
 ω_D = z-plane warped frequency

In searching the literature on the bilinear z-transform,^{3,4,5} another substitution is presented that is very similar to equation 31; that is

$$s \rightarrow \frac{z - 1}{z + 1} \quad (33)$$

with the warping function given as

$$W_A \rightarrow \tan\left(\frac{\omega_D T}{2}\right) \quad (34)$$

Occasionally this causes confusion since the units are not the same. In practice, however, both substitutions yield the same pole-zero configuration since the w/T terms will factor and cancel. This is best understood by making the respective substitutions in a general transfer function for a complex pole-pair such as

$$H(s) = \frac{w^2}{s^2 + 2\delta ws + w^2} \quad (35)$$

and comparing the z-plane pole positions that result.

When using the bilinear z-transform care must be taken when the break frequencies are near the half sampling frequency. An illustration of this fact and an appreciation of the warping required is best illustrated by an example. Table 2 shows various digital filter break frequencies and the required warped analog frequencies for a 1000 Hz sampling rate. Figure 15 shows graphically the non-linear frequency scale mapping of the bilinear z-transform.

Thus the bilinear z-transform is a powerful tool in digital filtering and may be utilized with either the partial fraction expansion or the rational fraction form of the Laplace transfer function. It is especially useful in MTI radar filters since the break frequencies of the high-pass and band-pass filters used are normally very low compared with the sampling frequency. This means that the warping is very small and the digital design very closely approximates the analog design.

Matched Z-Transform

The matched z-transform is somewhat of a compromise between the standard and bilinear z-transforms. It is an exponential mapping transform which gives a z-plane transfer function with poles and zeros matched to those of the continuous function.

Real poles or zeros are mapped using the substitution

$$s - a \rightarrow 1 - z^{-1} e^{aT} \quad (36)$$

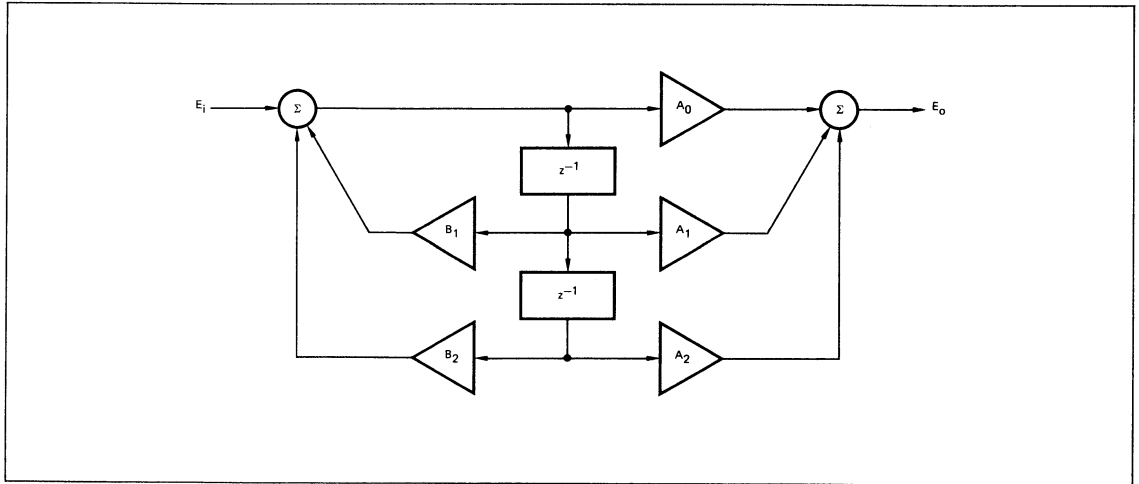


Figure 13. Recursive Two-Pole Structure.

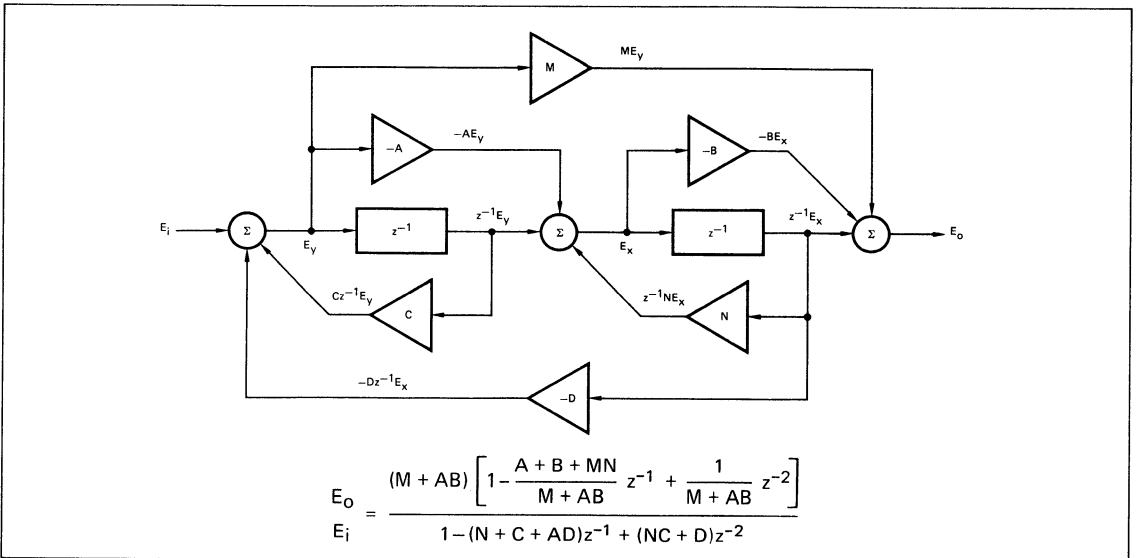


Figure 14. General Two-Pole Building Block.

while complex poles or zeros are mapped using the substitution

$$(s - a)^2 + b^2 \rightarrow 1 - 2z^{-1} e^{aT} \cos(bT) + z^{-2} e^{2aT} \quad (37)$$

The resulting z-plane transfer function is normally factored into numerator and denominator polynomials that are easily implemented using one and two-pole building blocks in the cascade canonical form.

The matched z-transform yields the same pole configuration as the standard z-transform; however, the zero configuration may require some modification to give satisfactory results. This usually entails the addition of zeros at the half sampling frequency ($z = -1$) to give the desired result.⁸

TABLE I. Standard z-Transform Substitutions.

f(t)	F(s)	F(z)
e^{-at}	$\frac{1}{s + a}$	$\frac{z}{z - e^{-aT}}$
$\sin(\omega_0 t)$	$\frac{\omega_0}{s^2 + \omega_0^2}$	$\frac{z \sin(\omega_0 T)}{z^2 - 2z \cos(\omega_0 T) + 1}$
$\cos(\omega_0 t)$	$\frac{s}{s^2 + \omega_0^2}$	$\frac{z(z - \cos(\omega_0 T))}{z^2 - 2z \cos(\omega_0 T) + 1}$

TABLE II. Digital Filter Warping Relation.

$$f_A = \frac{1}{\pi T} \tan(\pi f_D T) \quad T = 10^{-3} \text{ seconds}$$

Desired Digital Filter Break Frequency f_D Hz	Prewarped Analog Frequency f_A Hz	$\tan(\pi f_D T)$
50	50.5	.15838
100	103.2	.32492
200	231	.72654
250	318	1.0000
300	438	1.3764
400	978	3.0777
450	2010	6.3138
475	4050	12.706
500	?	∞

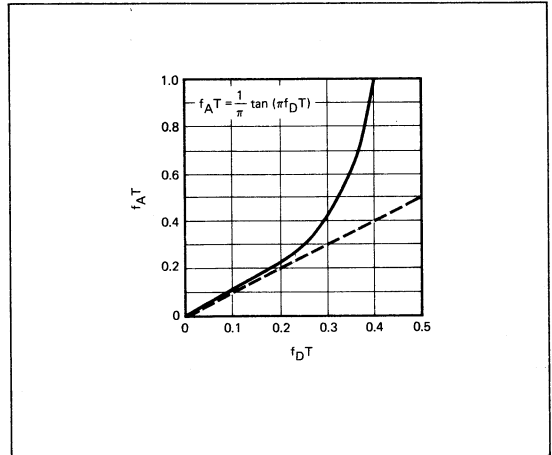


Figure 15. Bilinear z-Transform Frequency Scale Warping.

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5

DIGITAL FILTER DESIGN

By John R. Mick

There are several important considerations in determining parameters for the design of a digital filter. Many trade-offs exist in the selection of configuration, arithmetic, memory type, A/D converters, D/A converters etc. Some of the key parameters are examined here.

The most important single item in the digital filter design is the selection of the configuration. Because of this, an analysis of both a two-pole filter section and a single-pole filter section are presented here. The analysis concentrates primarily on the high-pass filter characteristics; however, it can also be performed on band-pass or low-pass recursive digital filters.

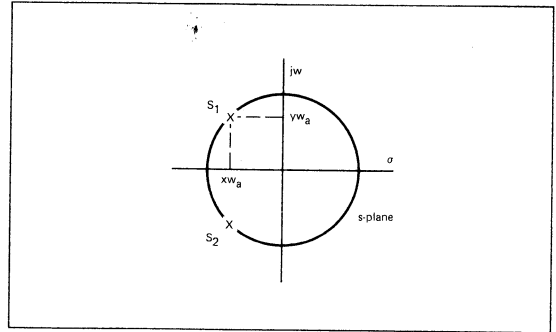


Figure 1. General Two-Pole s-Plane Plot.

COMPLEX POLE ANALYSIS

Since the implementation of many digital filters is typically a cascaded combination of two-pole sections composed of complex conjugate pairs of poles, it is important to examine this case in detail. The z-transform analysis of a normalized complex conjugate pair of poles in the s-plane follows and reveals several important equations for the design of digital filters.

Assume a general two-pole transfer function of

$$H(s) = \frac{K}{(s-s_1)(s-s_2)} \quad (1)$$

$$\text{where } s_1 = (-x + jy)w_a$$

$$s_2 = (-x - jy)w_a$$

such that these poles lie on a normalized unit circle in the s-plane and are scaled to their actual analog radian frequency by a multiplier w_a as shown in Figure 1.

Substituting s_1 and s_2 into $H(s)$, the transfer function is

$$H(s) = \frac{K}{(s + xw_a)^2 + (yw_a)^2} \quad (2)$$

Expanding the denominator of this transfer function and remembering that $x^2 + y^2 = 1$, the resultant transfer function becomes

$$H(s) = \frac{K}{s^2 + 2xw_a s + w_a^2} \quad (3)$$

This is similar to the usual textbook equation of

$$G(s) = \frac{K_0 w_n^2}{s^2 + 2\zeta w_n s + w_n^2} \quad (4)$$

Clearly, x is equivalent to ζ (zeta), the damping ratio, and w_a is equivalent to w_n , the resonant break frequency.

Since equation 3 describes a continuous analog function and since a digital filter usually is operating as a sampling system with a zero-order hold in the video channel before the filter, this continuous function is transformed to the z-plane for easier algebraic manipulation. Since high-pass filtering is to be described, the equivalent form of the bilinear z-transform is

used. Note that in a low-pass filter section, the zero locations do not affect the pole locations. This form uses the substitution, $s = (z-1)/(z+1)$. The z-plane transfer function becomes

$$H(z) = \left[\frac{K}{1+2xw_a+w_a^2} \right] \left[\frac{(z+1)^2}{z^2-2\left(\frac{1-w_a^2}{1+2xw_a+w_a^2}\right)z+\frac{1-2xw_a+w_a^2}{1+2xw_a+w_a^2}} \right] \quad (5)$$

where a gain multiplier factors from the transfer function when it is put in standard form. The poles in the z-plane are

$$z_1, z_2 = \frac{1-w_a^2 \pm j2w_a\sqrt{1-x^2}}{1+2xw_a+w_a^2} \quad (6)$$

Also, it is important to recognize that when using the bilinear z-transform, the analog radian break frequency w_a must be prepwarped by the relation

$$w_a = \tan\left(\frac{w_D T}{2}\right) = \tan(\pi f_D T) \quad (7)$$

where f_D is the desired break frequency of the digital filter and T is the sampling interval. The prepwarping is a function of the sampling rate which means that as the sampling rate is changed, the pole locations of the transfer function change. The transfer function derived in equation 5 is equivalent to the z-transform of a second order difference equation. This difference equation is

$$H(z) = \frac{A_0 + A_1 z^{-1} + A_2 z^{-2}}{1 - B_1 z^{-1} - B_2 z^{-2}} \quad (8)$$

which can be rearranged to eliminate A_2 and the variables renamed for convenience as

$$H(z) = G \left[\frac{B + Az^{-1} + z^{-2}}{1 - Cz^{-1} + Dz^{-2}} \right] = G \left[\frac{Bz^2 + Az + 1}{z^2 - Cz + D} \right] \quad (9)$$

The DC gain ($z = 1$) of this transfer function is

$$\text{DC Gain} = G \left[\frac{B + A + 1}{1 - C + D} \right] \quad (10)$$

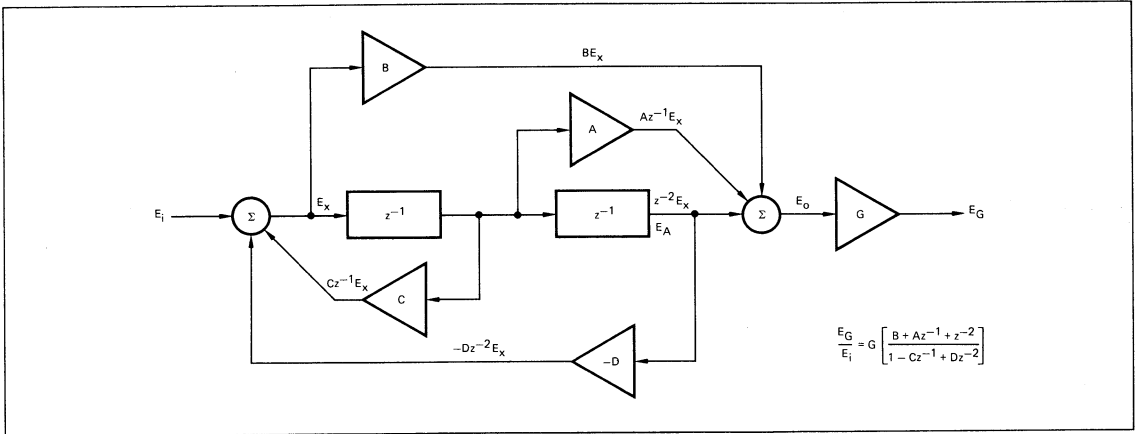


Figure 2. Canonical Two-Pole Digital Filter Implementation.

Implementation of this transfer function is shown in Figure 2.

This analysis results in the general z-plane transfer function of equation 5 that is equivalent to the general s-plane transfer function for a complex conjugate pair. The transfer function of equation 5 determines the numerical values for the multipliers in the digital design and yields a digital filter that is equivalent to its analog counterpart.

INTERNAL MAGNIFICATION – CANONICAL FORM

The internal magnification within the digital filter building block is analyzed to determine the number of additional storage bits that must be provided in memory over and above the input quantization number of bits. This is accomplished by deriving the internal transfer function at each memory input (or output) and computing the peak magnification expected. Also, by setting $z = 1$, the DC magnification is determined.

The internal transfer function at the memory output within the filter of Figure 2 is

$$\frac{E_A}{E_i} = \frac{z^{-2}}{1 - Cz^{-1} + Dz^{-2}} = \frac{1}{z^2 - Cz + D} \quad (11)$$

The magnitude squared of this internal transfer function is computed by multiplying the denominator polynomial by its complex conjugate. That is

$$\left| \frac{E_A}{E_i} \right|^2 = \frac{1}{(z^2 - Cz + D)(z^{*2} - C^*z^* + D)} \quad (12)$$

which results in

$$\left| \frac{E_A}{E_i} \right|^2 = \frac{1}{1 + C^2 + D^2 + 2D \cos(2wT) - 2C(D + 1) \cos(wT)} \quad (13)$$

Differentiating the denominator with respect to w and setting the result equal to zero yields

$$\frac{d(\text{DENOM})}{dw} = 0 = +2TC(D + 1) \sin(wT) - 4DT \sin(2wT) \quad (14)$$

Thus, the frequency at which the peak internal magnification is reached is

$$\cos(wT) = \frac{C(D + 1)}{4D} \leq 1.0 \quad (15)$$

$$f = \frac{1}{2\pi T} \cos^{-1} \left(\frac{C(D + 1)}{4D} \right) \quad (16)$$

Computing the peak magnitude at this frequency using the squared magnitude function yields

$$M_A = \left| \frac{E_A}{E_i} \right| = \frac{1}{\sqrt{\left(1 - \frac{C^2}{4D}\right) (1 - D)^2}} \quad (17)$$

which is the maximum magnification within this two-pole building block. One extra bit must be provided in both memories of this filter for each factor of two or fraction thereof as computed in this magnification for stable operation of the filter. Figure 3 shows the upper right hand quadrant of the z-plane, with contours of constant magnification factor, M , (same as M_A) plotted thereon. The lower right hand quadrant is the mirror image of this plot since the poles appear as complex conjugate pairs.

The pole locations as seen from equation 11 for the internal transfer function of this filter are

$$z_1, z_2 = \frac{C}{2} \pm j \frac{\sqrt{C^2 - 4D}}{2} \quad (18)$$

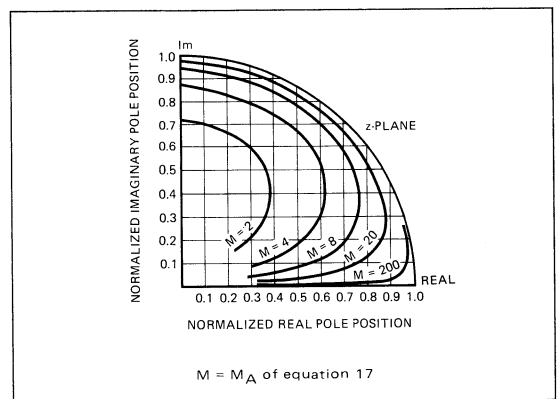


Figure 3. Peak Gain of Canonical Two-Pole Digital Filter for Pole Position in the z-Plane.

where $|4D| > |C^2|$

A typical plot of these poles is shown in Figure 4. As these poles are moved toward the point $z = 1$ in Figure 4, the break frequency of the filter is lowered with respect to the sampling rate. From this, it can be seen that the real part of the pole is approaching 1.0; thus, the value of C is approaching 2.0. Likewise, the imaginary part of the pole is approaching 0.0; thus, the absolute value of $C^2 - 4D$ is approaching zero. Since C is near 2.0, D is approaching 1.0 for this condition. When these values of $C = 2$ and $D = 1$ are inserted into the maximum magnification equation, it is found that the peak value goes to infinity. This is easily checked by looking at the DC gain of the internal transfer function by substituting $z = 1$; it is

$$M_D = \left. \frac{E_A}{E_i} \right|_{z=1} = \frac{1}{1-C+D} \quad (19)$$

and for $C = 2.0$ and $D = 1.0$ is found to be infinite. The internal DC magnification for this two-pole building block is plotted as a function of pole position in Figure 5 for the upper right hand quadrant of the z -plane. The lower right hand quadrant is the mirror image since the poles occur in complex conjugate pairs.

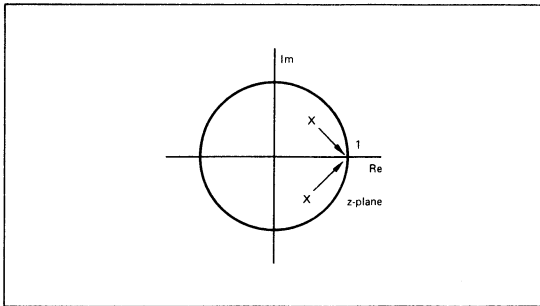


Figure 4. Internal z -Plane Pole Location of Two-Pole Section.

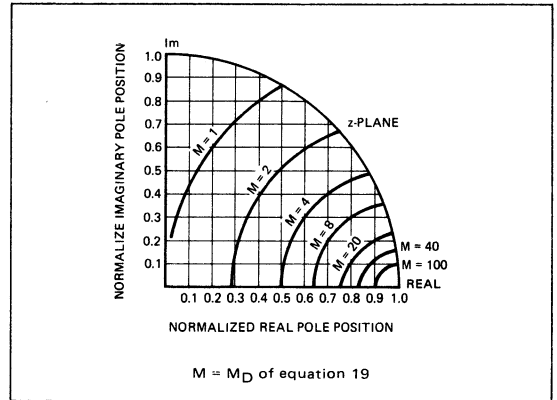


Figure 5. DC Gain of Canonical Two-Pole Digital Filter for Pole Position in the z -Plane.

Notice the DC gain of this memory element is not a function of the coefficient values but is

$$\left. \frac{E_B}{E_i} \right|_{z=1} = \frac{D+1-C}{1-C+D} = 1 \quad (22)$$

The frequency at which the peak magnitude within this part of the filter occurs is

$$\cos(\omega T) = \alpha = \frac{-(D^2 + (1-C)^2)}{2D(1-C)} \pm \frac{\sqrt{(D^2 + (1-C)^2)^2 - (1-C)[CD(C-3D) - C(1-C)^2 - D(1-D)^2]}}{2D(1-C)} \quad (23)$$

$$f = \frac{1}{2\pi T} \cos^{-1}(\alpha) \quad (24)$$

The peak magnitude reached at this frequency is

$$M_B = \left| \frac{E_B}{E_i} \right| = \frac{\sqrt{(1-C)^2 + D^2 + 2D(1-C)\cos(\omega T)}}{\sqrt{(1-D)^2 + C^2 - 2(C+D)\cos(\omega T) + 4D\cos^2(\omega T)}} \quad (25)$$

Examining the transfer function E_B/E_i shows that a discontinuity exists at $C = 1$. Here the internal transfer function reduces to

$$H(z) = \frac{D}{z^2 - Cz + D} \quad (26)$$

The peak frequency of $H(z)$ for this condition can be determined from

$$\cos(\omega T) = \frac{(1+D)}{4D} \leq 1.0 \quad (27)$$

and the peak magnitude at this frequency is

$$M_B \Big|_{C=1} = \left| \frac{E_B}{E_i} \right| = \frac{D}{\sqrt{(1-D)^2(1-\frac{1}{4D})}} \quad (28)$$

The internal transfer function at the output of the second memory word of the filter in Figure 6 is

$$\frac{E_F}{E_i} = H(z) = \frac{1-z}{z^2 - Cz + D} \quad (29)$$

INTERNAL MAGNIFICATION – IMPROVED FORM

The canonical form two-pole, two-zero building block yields an internal transfer function that requires an increasing number of extra storage bits as the cut-off frequency is lowered with constant sampling rate. As the cut-off frequency is designed nearer to zero, the required extra bits can easily be five or ten times the total input quantization number of bits. This has an almost direct effect on the cost of the processor. Therefore, it is essential that a configuration is found that minimizes the internal magnification. The digital filter shown in Figure 6 has this characteristic. The improvement is provided by the zero that is in the internal transfer function. This tends to cancel the effect of the poles and greatly reduces the internal magnification.

The analysis of the filter configuration of Figure 6 demonstrates the improvement realized. The overall filter transfer function is

$$H(z) = \frac{(z-1)^2}{z^2 - Cz + D} \quad (20)$$

The internal transfer function at the output of the first memory is

$$\frac{E_B}{E_i} = \frac{D+z(1-C)}{z^2 - Cz + D} \quad (21)$$

Filter Coefficients		z-Plane		Canonical Magnification		Improved Form			
C	D	Real	Imag.	DC	Peak	Memory #1		Memory #2	
						DC	Peak	DC	Peak
62/32	31/32	.97	.17	32.0	181.0	1.0	31.2	0.0	32.3
61/32	31/32	.95	.17	32.0	90.9	1.0	15.1	0.0	16.1
60/32	29/32	.94	.17	32.0	61.4	1.0	9.7	0.0	10.7
58/32	27/32	.91	.15	32.0	39.0	1.0	5.4	0.0	6.4
54/32	23/32	.84	.08	32.0	32.0	1.0	2.6	0.0	3.6
50/32	20/32	.78	.12	32.0	16.0	1.0	1.7	0.0	2.7

Table 1. Magnification Examples

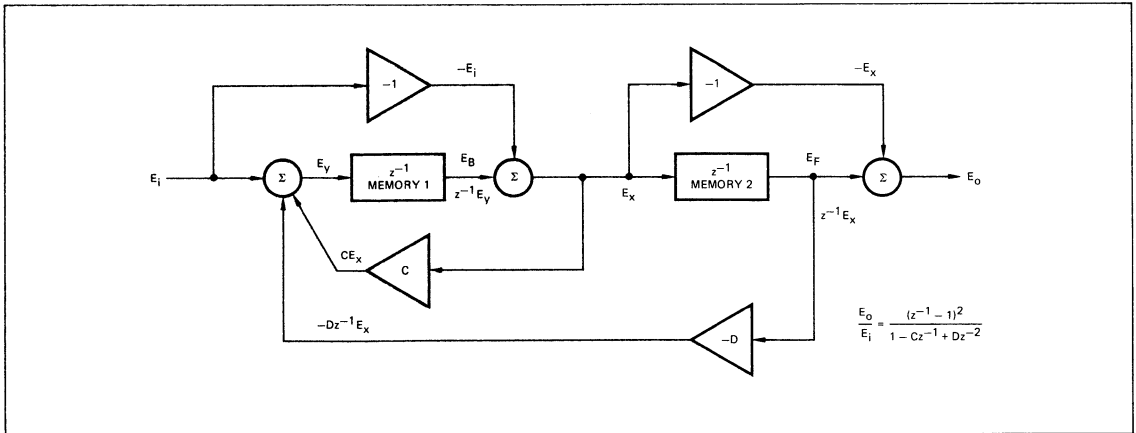


Figure 6. Improved Two-Pole Digital Filter.

The DC gain ($z = 1$) of this memory element is zero—a marked improvement from the canonical form. The frequency at which the peak magnitude occurs in this memory can be computed from

$$\cos(\omega T) = 1 \pm \frac{C-1+D}{2\sqrt{D}} \leq 1.0 \tag{30}$$

the peak magnitude reached at this frequency is

$$M_F = \left| \frac{E_F}{E_i} \right| = \sqrt{\frac{2-2\cos(\omega T)}{(1-D)^2 + C^2 - 2(C+CD)\cos(\omega T) + 4D\cos^2(\omega T)}} \tag{31}$$

An example of the improvement offered by the filter in Figure 6 is shown in Table 1 where the results of several examples using these equations are tabulated. As a result of this analysis it is obvious that an improved form of filter configuration exists. The equations are readily programmed on a general purpose digital computer to assist in the design phase by carrying out the computations for various arithmetic coefficients.

SINGLE POLE ANALYSIS

For systems where an odd number of poles in the digital processor provides acceptable performance, at least one real pole is required in the digital filter transfer function. To analyze this condition consider the s-plane plot for a single high-pass section. A “zero” is located at zero and a “pole” is located at $-a$ on the real axis in the s-plane as shown in

Figure 7a. The resultant s-plane transfer function for the high-pass section is

$$H(s) = \frac{s}{s+a} \tag{32}$$

Using the equivalent bilinear form of the z-transform, the z-plane transfer function is

$$H(z) = \left(\frac{1}{1+a} \right) \left[\frac{z-1}{z + \frac{(a-1)}{(a+1)}} \right] \tag{33}$$

and the pole and zero are plotted in Figure 7b. As in the two-pole analysis, the frequency scale must be prewarped due to the non-linear transformation to achieve the desired digital filter implementation

$$a = \tan\left(\frac{\omega_D T}{2}\right) \tag{34}$$

where a = design s-plane radian frequency
 ω_D = desired digital filter cut-off radian frequency

Figure 8 shows a one-pole, one-zero digital filter implementation where the z-plane transfer function is

$$H(z) = \frac{z-1}{z-C} \tag{35}$$

5

Digital Filter Design

The coefficient C is determined from

$$C = \frac{1-a}{1+a} \quad (36)$$

If the overall transfer function gain of the digital filter is critical, a gain multiplier equal to $1/(1+a)$ must be placed after the single-pole section. The internal transfer function of this single-pole cell at the memory output E_A is

$$\frac{E_A(z)}{E_i(z)} = \frac{z^{-1}(1-C)}{1-Cz^{-1}} = \frac{1-C}{z-C} \quad (37)$$

The peak gain occurs at DC for this filter and is computed by setting $z = 1$. For this filter configuration the DC gain is unity.

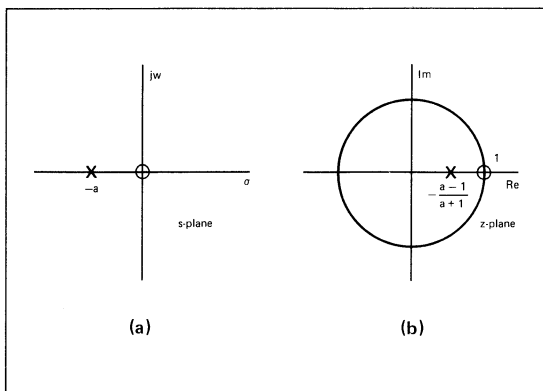


Figure 7. Single-Pole s-Plane and z-Plane Plot.

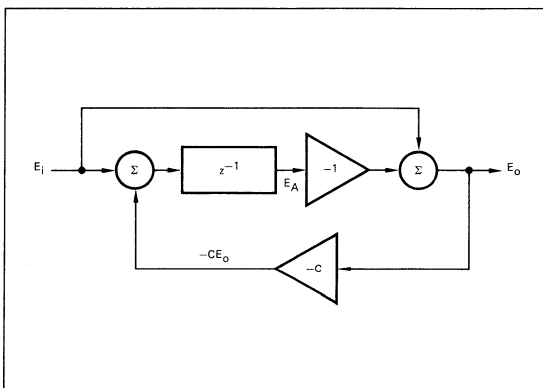


Figure 8. Single-Pole, Single-Zero Digital Filter.

ARITHMETIC

Once the digital filter configuration is selected, several other decisions must be made concerning the actual operations within this configuration. These decisions regarding the numbering system, arithmetic, multipliers etc. influence each other; however, throughout this discussion they are considered independently.

The first of these decisions is the binary number system used. Since the arithmetic to be performed by the digital processor includes addition, subtraction, and multiplication of both

positive and negative numbers, the two's complement numbering system is the best binary representation system for real-time digital processors. The two's complement representation is utilized throughout the digital filter as long as a bipolar numbering quantization scheme is required.

The coefficient multipliers C, D and G of Figure 2 can be easily implemented using the Am25LS14 serial/parallel multiplier. Likewise, the additions and subtractions required can be performed using the Am25LS15 quad serial adder/subtractor. The basic signal flow is shown in Figure 9. This figure is an oversimplification since it does not show all the timing and control as well as the delays required in the data path to enable the serial data to arrive at the appropriate adder inputs at the necessary sequence time. The figure does show the basic architecture required to implement the canonical two-pole, two-zero building block using the Am25LS14 and Am25LS15. Also the figure does demonstrate a key point. That is, the entire arithmetic section (assuming 8-bit coefficients) can be implemented using five Am25LS14's and one Am25LS15; a significant hardware reduction compared to any other implementation scheme. The delays, timing and control can be designed as required for each application.

The hardware required to implement the improved two-pole, high-pass filter depicted in Figure 6 is demonstrated in Figure 10. Here the required single flip-flop delay in the serial data path is shown. Thus all memories, multipliers, adder/subtractors and the D-type flip-flop can be clocked in unison and the LSB's reach the data path inputs in synchronism throughout the algorithm.

This two-pole, high-pass filter arithmetic section is implemented using only one Am25LS15 and two Am25LS14's for 8-bit C and D coefficients. The memory length can be as required for the design accuracy of the application. This example assumes that the digital number range has the required dynamic range to handle the maximum expected magnification within the filter. Round-off, truncation, overflow etc. can be handled in other ways as required by the design. If round-off is required an additional adder section can be placed in front of the memory and plus one added at the appropriate bit to perform the rounding. A microprogrammed state-machine approach is recommended as the control means to provide the required input signals and timing. Likewise one section of an Am25LS15 adder can be used to detect overflow if required.

The single-pole, single-zero digital filter section as shown in Figure 8 can also be easily implemented using the Am25LS14, Am25LS15 and the serial memory as required.

From these examples it is seen that the Am25LS14 and Am25LS15 can be used to perform all multiplication, addition and subtraction required in a digital filter algorithm implemented in serial/parallel hardware. While not specifically discussed in these examples, it should be recognized that the Am25LS22 and Am25LS299 are also applicable to the memory portions of the filters. However care must be exercised when using the sign extend feature of the Am25LS22 so that data for the next cycle is not lost.

For example the first memory (left hand side) of Figure 10 can be implemented using a single Am25LS22 (8-bit truncated word).

The second memory (right hand side), however, requires an Am25LS22 preceded by an Am25LS299 (or another Am25LS22) so that the data out of the first adder can be retained while the sign extend function is being performed in this memory.

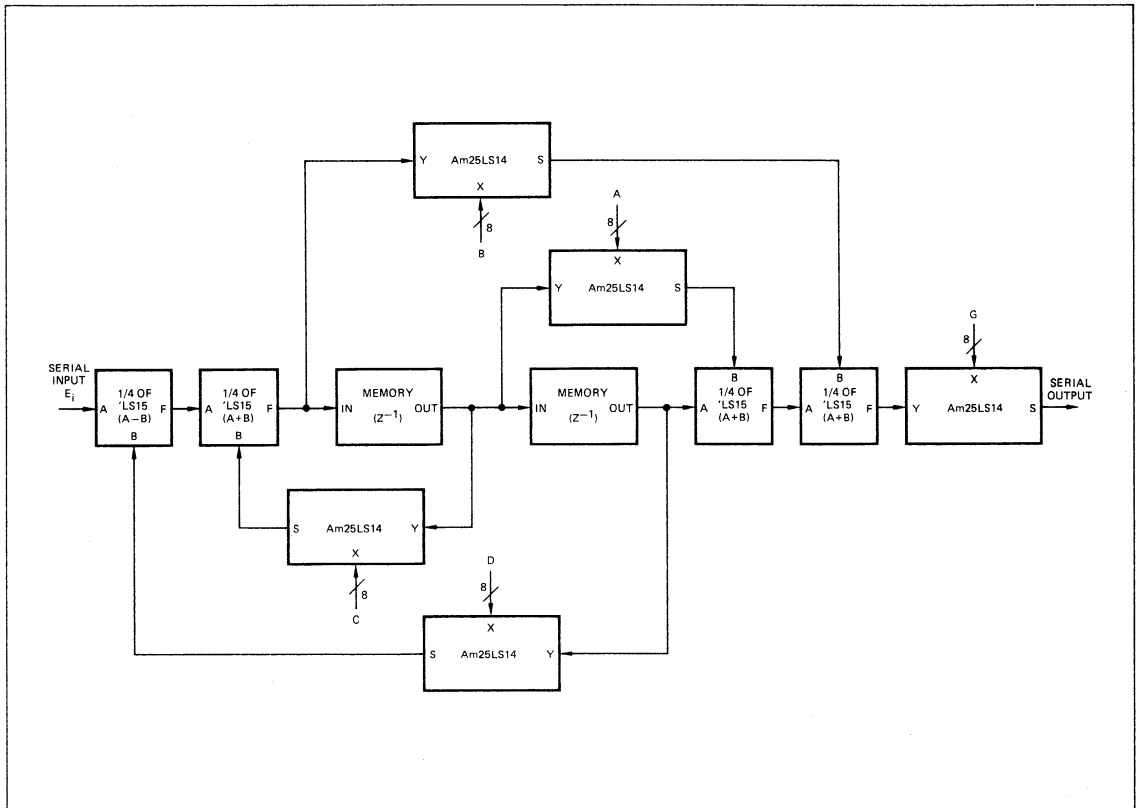


Figure 9. Canonical Two-Pole, Two-Zero Recursive Digital Filter Using the Am25LS14 and Am25LS15.

FILTER GAIN

The s-plane transfer function for a complex pair of poles yields a z-plane transfer function from which a gain multiplier is factored as shown in equation 5 and is

$$\frac{K}{1 + 2 \times w_a + w_a^2} \tag{38}$$

While the K is in the initial s-plane transfer function assumption, the quantity $1/(1 + 2 \times w_a + w_a^2)$ is a constant that must be recognized as it is usually greater than 1.0. This means that in the cascade two-pole, building-block approach, the maximum input dynamic range to each section is increasing by this quantity. Therefore a gain coefficient multiplier may be required between each two-pole building block to reduce the input dynamic range to the original A/D converter output equivalent. Likewise the gain at any point throughout the filter can be modified if the designer desires using the gain multiplier approach.

Another form of gain that must be considered in the cascade implementation is the order in which the two-pole sections are placed. It is desirable to place the over-damped poles first in the cascade configuration followed by the under-damped poles. The reason for this requirement is that the under-damped pole pair transfer function has gain at or near the pole pair cut off frequency and thus the input dynamic range to the next cascaded section is magnified.

OTHER CONSIDERATIONS

In addition, there are other areas the designer can investigate in detail while designing digital filters. The most notable of these is the response of the filter to internal and external noise. It is not the intent of this application note to develop the general theory of noise in digital filters since to some extent that already exists in the literature^{1,2,3,4,5}.

Another consideration regards the A/D converter. The dynamic range of the A/D converter is selected as required where each bit provides six db dynamic range. The variance of the quantization steps (noise) associated with the A/D converter can be shown⁵ to be

$$\sigma^2 = \frac{E^2}{12} \tag{4-1}$$

where E is the quantization step. If the A/D converter is selected as having eight bits, E² has 48 db range and the quantization noise power is a factor of 12 (11 db) below this level.

Also of importance is the noise due to the multiplication truncation effect, sometimes called the "deadband" effect. Basically this noise causes the internal values within the filter to terminate prematurely. That is, the same steady-state value is not reached as could be reached if infinite-precision arithmetic is used. The easiest demonstration of this effect is to examine the actual hardware response (or computer simula-

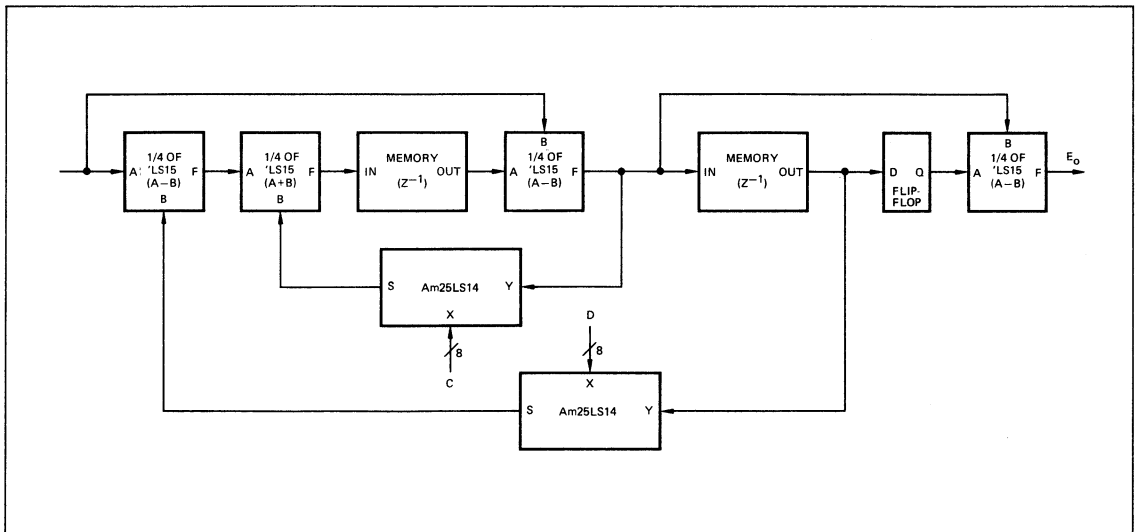


Figure 10. Two-Pole, High-Pass Recursive Digital Filter.

tion) of a high-pass filter to an impulse input. After several iterations the filter will "hang up" as the edge of the deadband is reached. Thus it will not decay to zero as might be expected.

Another effect which can sometimes result with a constant input is that a small steady-state oscillation can occur. Typically this behavior occurs as a low amplitude square wave with frequency of $PRF/2$. The cause of this oscillation is due to noise components which are introduced at the various multipliers within the filter each time the algorithm is iterated; the filter then magnifies the component at $PRF/2$.

These intricacies demonstrate the need for exhaustive computer simulation of the filter, once designed, to insure operation as desired. Simple Fortran math model programs that allow multiplier and memory truncation as well as A/D quantization effects to occur can quickly demonstrate the various characteristics of the filter.

TEST EQUIPMENT

One of the most important areas the digital designer must make provision for in the design of a digital filter is the ability to test the various components of the filter (adders, multipliers etc.) after the hardware is constructed. Two techniques can be applied in this application where each gives a partial testing capability. These two techniques are static testing and dynamic testing using special purpose test equipment.

The digital filter should be designed to provide easy access to test points that contain data lines to all of the bits in a complete word. In this manner the complete word including sign is available to the special test set which contains both static readout capability and dynamic readout capability.

Provision should be made in the design to allow any dynamic memories to be replaced by static memories. Thus the digital filter can be "single stepped" such that the outputs of the multipliers and adders can be monitored on readout devices such as lamps or octal display tubes. These readouts can be checked against a computer printout of an exact simulation of the digital filter and the test set. This gives the capability of

tracing any defective components or wiring errors in the equipment. Manual switches are used to enter data into the filter and then the filter "stepped along." The corresponding output states are observed to demonstrate that no deviation occurs from the computer tabulation. This is equivalent to checking either the step response or the impulse response of the filter in slow motion depending on the input switch manipulation.

In dynamic testing, digital-to-analog (D/A) converters within the test set can be plugged into the same test points as used in the static mode. The output from the D/A converter is an analog signal viewable on an oscilloscope. Thus, the operation of the filter at various points can be checked at normal operating frequencies and the results observed to determine compliance to the desired performance. In the dynamic mode, the step response, impulse response or Bode response can be determined.

It is important in working with digital filter designs to have a comprehensive test plan included as part of the design. If this is not done, it is almost impossible to "trouble-shoot" such a complex piece of equipment and the desired operation may never be completely verified.

- ¹Rader, C. M., and B. Gold, "Effects of Quantization Noise in Digital Filters," (1966 Spring Joint Computer Conference, AFIPS Proceedings, Vol. 28, 1966), pp. 213-219.
- ²Jackson, L. B., "On the Interaction of Roundoff Noise and Dynamic Range in Digital Filters," (Bell System Technical Journal, Vol. 49, No. 2, February, 1970), pp. 159-184.
- ³Knowles, J. B., and E. M. Olcayto, "Coefficient Accuracy and Digital Filter Response," (IEEE Transactions on Circuit Theory, Vol. CT-15, March, 1969), pp. 31-41.
- ⁴Koivo, A. J., "Quantization Error and Design of Digital Control Systems," (IEEE Transactions on Automatic Control, Vol. 1, February, 1964), pp. 55-58.
- ⁵Gold, B., and C. M. Rader, *Digital Processing of Signals*, (McGraw-Hill, Inc., New York, 1969), Ch. 4.

AIRBORNE MTI RADAR- A Digital Filter Application Example

By John R. Mick

A typical non-coherent airborne MTI radar system is shown in Figure 1. This system transmits an RF pulse of width τ at a carrier frequency of f_0 that has a wave length λ . The receiver output is a video signal representing the echo return power of the ground patch that is defined by the antenna beam width, transmitter pulse width, and depression angle from the aircraft. This received signal contains both the fixed-target and moving-target information from each range cell. The fixed-target return is termed "clutter" since it represents the unwanted signal. The moving-target echo causes a doppler frequency envelope on the received signal and this doppler frequency is

$$f_d = \frac{2 V_r}{\lambda} \cos(\theta)$$

where

- f_d = doppler frequency in Hz
- V_r = velocity of target in m/sec
- λ = wave length of transmitted frequency in m
- θ = angle between radar antenna boresight and target velocity vector

The MTI processor detects the moving-target doppler in the received video signal while rejecting the fixed-target clutter return by using a range-gated, high-pass filter. The term "range-gating" refers to the technique of applying individual segments of ground patch echo to corresponding individual high-pass filter elements. The range-gated processor can extract moving-target echos from the clutter return even if the clutter

echo is 20 or 30 db greater than the moving-target echo signal.⁷ The output of the MTI processor is displayed on an appropriate display such as a cathode ray tube or solid state display.

"Clutter is distinguished from receiver noise by its relatively narrow, low-frequency spectrum, which implies that these echoes are correlated from one sample to the next. Because of this property it is possible to reduce the effects of clutter with filters that reject energy at the clutter frequencies but that pass the doppler-shifted echoes from targets having higher velocities than the clutter. A processor that distinguishes moving targets from clutter by virtue of differences in their spectra is called a moving target indicator or simply MTI!"⁶ The clutter spectral spread is effected by aircraft motion, antenna scanning, and radar imperfections. Radar imperfections include transmitted frequency change, amplitude modulation of the transmitted pulse, pulse width jitter, and time jitter between the trigger pulse and transmitted pulse. Also, the clutter is effected by wind effects on the surface terrain foliage such as trees and bushes.

The presence of a moving target within a range resolution cell causes an amplitude modulation of consecutive returns in that cell. A resolution cell has the width of the ground surface illuminated by the antenna azimuth beam width, and the length determined by the range resolution of the radar. After many returns, the resolution cell has an output waveform envelope defined by the moving-target doppler frequency f_d described by equation 1. The output spectrum after the envelope detector in the receiver is shown in Figure 2. Here, the video spectrum for a single cell consists of a large clutter return along with a moving target return.

Because of the spurious sidebands produced by the sampling process, the clutter spectrum is imaged at all integer multiples of the sampling rate, also known as the pulse repetition frequency (PRF). Due to the envelope detection process of the intermediate frequency (IF) signal, all doppler frequencies are found to be "folded" into the positive frequency range from DC to one-half the sampling rate (PRF/2). In addition the moving-target spectrum is found on each side of the clutter spectrum at all integer multiples of the PRF.

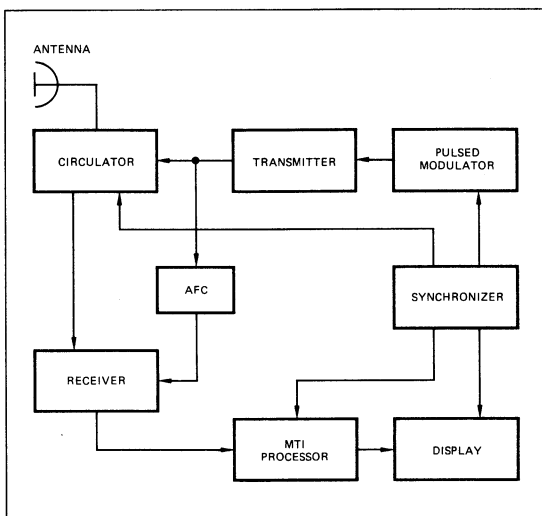


Figure 1. Typical Non-Coherent Airborne MTI Radar System.

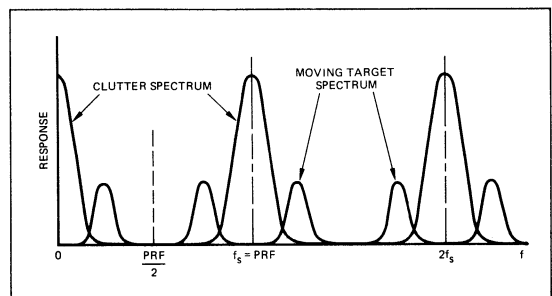


Figure 2. Receiver Output Spectrum.

DELAY LINE CANCELLERS

Historically, the first MTI detection device used to extract the moving-target doppler echo in the presence of clutter was the delay line canceller. Usually, it consisted of an analog delay line length $T = 1.0/PRF$ seconds and a subtractor as shown in Figure 3.

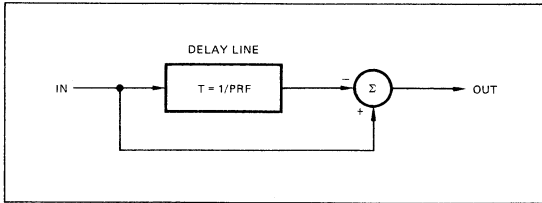


Figure 3. Single Delay Line Canceller.

Here, successive returns of the radar from the same range cell are subtracted resulting in an output that is equal to the pulse-to-pulse fluctuations of the radar return. Since fixed targets have a constant amplitude return, the output is zero in the ideal system. When a moving target is added, there is a variation of return amplitude from pulse to pulse as defined by the doppler frequency envelope; thus, an output related to this variation results from the delay line canceller for this range cell.

The amplitude response $H(f)$ for the single delay line canceller is

$$|H(f)| = K |\sin(\pi Tf)|$$

where T is the sampling interval, f is the input frequency, and K is a gain constant. Thus the delay line canceller has a transfer response that is a function of the inter-pulse period and is zero at DC and integer multiples of the PRF as shown in Figure 4.

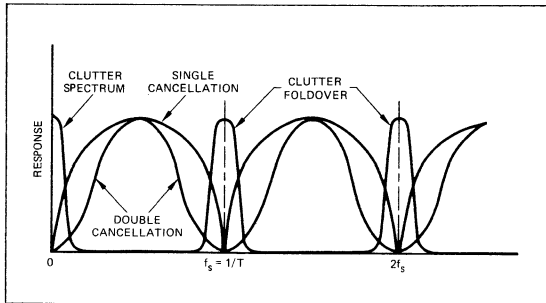


Figure 4. Frequency Response of Single-Delay-Line Canceller and Double-Delay-Line Canceller.

A double delay line canceller can be used to increase the clutter rejection of an MTI system. Figure 5 shows two equivalent forms of a double delay line canceller. The z^{-1} notation is the unit delay operator and refers to a delay equal to one interpulse period of the radar. Each canceller has the transfer function

$$\frac{E_o}{E_i} = (z^{-1} - 1)^2 = \frac{(z-1)^2}{z^2}$$

The amplitude response for these cancellers is

$$|H(f)| = K_1 |\sin^2(\pi Tf)|$$

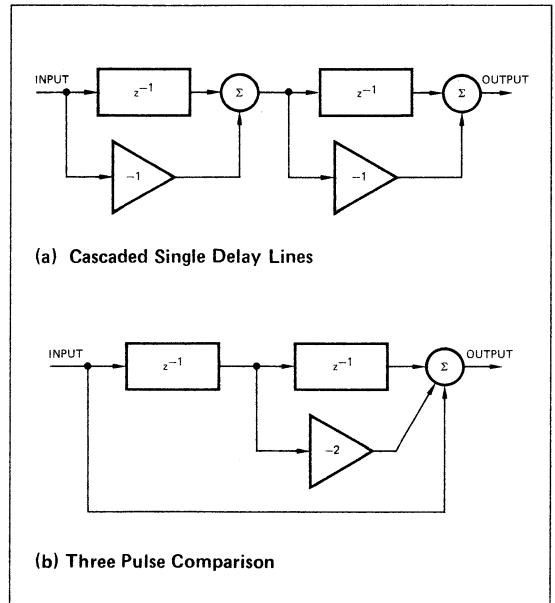


Figure 5. Double Delay Line Canceller.

As is seen, the double delay line canceller has a sine-squared response rather than the sine response of a single delay line canceller as shown in Figure 4. As a result, a greater attenuation of the clutter spectrum is realized. It is possible in theory to combine three, four or more delay lines in various configurations to give multiple zeros at the origin in the s -plane. However, these become very difficult to implement since very slight changes in delay time cause significant reductions in cancellation. Even the double delay line canceller is difficult to implement reliably.

ANALOG RANGE-GATE FILTER

The analog range-gated filter represents a more sophisticated radar technique for separating moving target returns from fixed target returns by detection of the doppler shift in frequency due to the target motion. The combinations of a moving target or targets with a larger fixed target within a resolution cell causes an amplitude modulation of consecutive returns from that cell.⁷

A block diagram of a simple analog range-gated filter is shown in Figure 6. Here input switch S_1 and output switch S_2 are closed simultaneously for a period equal to the radar pulse width τ .

This causes the radar echo return for the range cell to be stored on capacitor C_1 . The final voltage on C_1 each time switch S_1 closes, is equal to the instantaneous value of the radar video input at the end of each sampling interval τ . Therefore, the input switch and capacitor form a zero order hold circuit. After input switch S_1 is opened, the analog voltage equal to the return echo will remain as an input to filter number one. At the same time, the output switch S_2 applies the present output of the filter to the output line.

DIGITAL RANGE-GATED PROCESSOR

A digital range-gated processor is a highly sophisticated radar technique for extracting moving target echoes. The digital range-gated filter performs the identical function as the analog range-gated filter; however, the hardware implementation of the two types of filters is notably different.

A block diagram of a simple digital range-gated processor is shown in Figure 8. Here input switch S_1 is closed for τ seconds to store the final instantaneous value of the radar return echo voltage for the first range cell on capacitor C_1 . When switch S_1 is opened switches S_2 and S_3 are closed. The second range cell video return is stored on capacitor C_2 . Thus, switches S_1 and S_3 along with capacitors C_1 and C_2 provide two first order hold circuits. Meanwhile switch S_2 applies the voltage on C_1 to the analog-to-digital (A/D) converter. In the A/D converter the analog voltage is quantized to a binary number representation. After τ seconds, S_2 and S_3 are opened and S_1 and S_4 are closed resulting in similar action. This process of alternating the S_1, S_4 pair and the S_2, S_3 pair continues until the desired range is covered by the processor and each resolution cell echo return in quantized.

The binary output from the A/D converter is applied to the digital filter which, in effect, consists of N individual filters as in the previous analog example. Here, however, the arithmetic circuitry is implemented only once and is time shared among all filter elements in the processor. This is easily achieved since the individual filters operate sequentially. The output of each individual filter element is applied sequentially to the digital-to-analog (D/A) converter resulting in a continuous video MTI output synchronous in range with the radar video input.

One of the key advantages of the digital filter is that the arithmetic operations are all handled by the same hardware for each filter cell. This means each individual filter element has exactly the same transfer function. That is, each has exactly the same mid-band gain, cut-off frequency, and attenuation. In the case of individual analog filters, amplifier gains tend to differ and component values vary initially as well as with temperature and age.

A digital memory word is required for each pole of each cell in the range-gated processor and no sharing is possible. The analog equivalent of this is the storage supplied by capacitors and inductors, since these are the components that provide the terms (sL and 1/sC) associated with the poles in the Laplace transfer function. Many additional advantages of the digital filter approach to MTI radar exist. These will become apparent as the design criteria are examined in more detail.

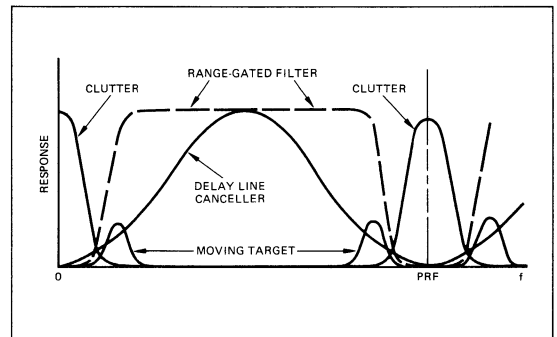


Figure 7. Spectral Response of Filter Element.

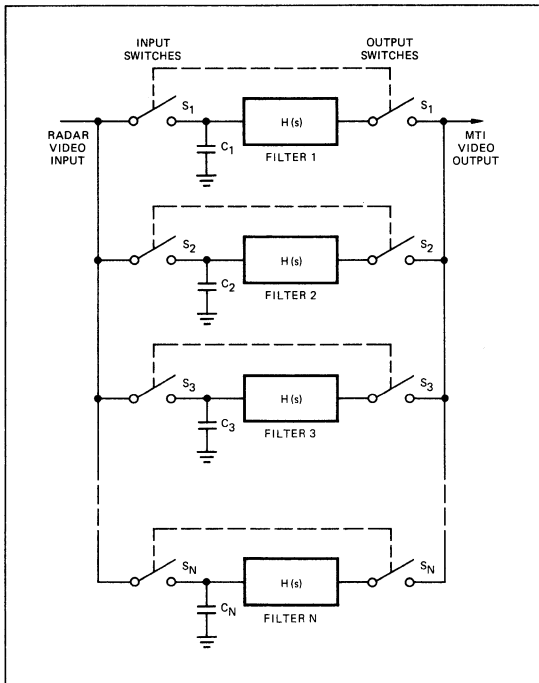


Figure 6. Simple Analog Range-Gated Filter.

At the instant switches S_1 are opened, switches S_2 are closed for τ seconds and action similar to that described above takes place. Likewise, when switches S_2 are opened, switches S_3 are closed and this continues sequentially until switches S_N are activated.

As is seen, each filter element receives radar echo return from successive range cells approximately equivalent of $c\tau/2$ in range since a two-way trip is required for the radar energy and where c equals the speed of light. Thus each analog filter is gated to receive a small range patch of radar echo return; thereby, the name analog range-gated filter is derived.

One important aspect of this type of MTI system is that since the filters are time multiplexed, the resolution cells are essentially independent. However successive returns are highly correlated since they represent echoes from essentially the same ground patch. The filter element used to extract the moving target doppler is designed to provide a very sharp rejection of the clutter spectrum while providing near uniform gain to the widest possible band of frequencies containing moving target echoes. This is accomplished with a sharp cut-off high-pass filter, usually with at least 24 db per octave attenuation. The amplitude response of the filter in one element of a range-gated filter is shown in Figure 7 and is compared with the response of a single delay line canceller.

There are many variations that can be derived from the basic analog range-gated filter shown in Figure 6. These include input and output multiplexing schemes to reduce switching speed requirements, various analog filter cut-off frequency control techniques to allow the widest possible acceptance band for moving target frequencies as determined by the spectral spread of the clutter return, etc. Each configuration is still basically a device to separate the moving-target signal spectrum from the fixed-target signal spectrum.

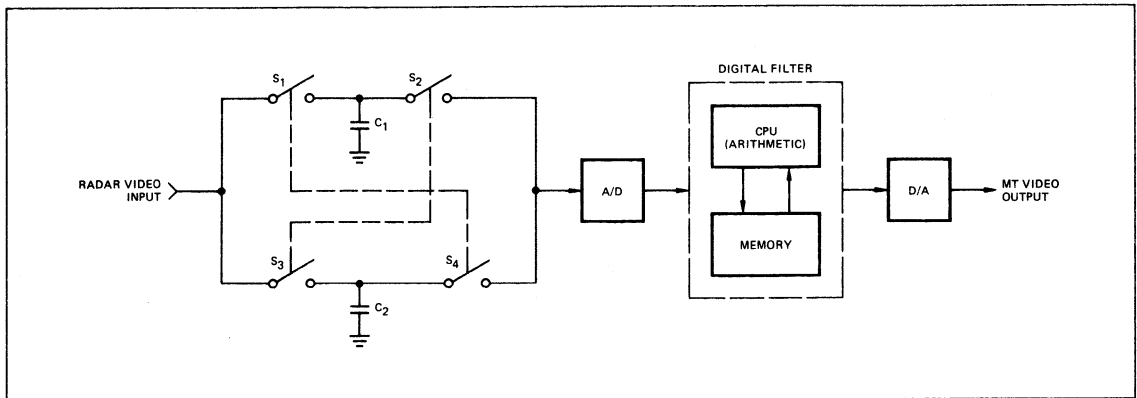


Figure 8. Simple Digital Range-Gated Processor.

SUMMARY

Chronologically the delay line cancellers were the first MTI detection devices for pulse-doppler radar systems. An improvement in detectability was added to the system by the use of the analog range-gated filter. This improvement is related to the sharper filter cut-off characteristic which increases the rejection to clutter. Likewise, additional canceller gain is supplied to the doppler signal from slower moving targets.

The most recent improvement in MTI radar processors is a result of the digital implementation of the range-gated processor. The improvement is provided by several features inherent in the digital filter design. These include: the uniform gain provided by all cells of the processor, the ability to move the cut-off frequency to various points near the clutter spectrum, the freedom from variations due to parts aging, and the reduced size and power afforded by arithmetic time sharing.

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Understanding Booth's Algorithm in 2's Complement Digital Multiplication

By John R. Mick

INTRODUCTION

At the present time, digital machines perform multiplication using either serial techniques, serial-parallel techniques, or all-parallel techniques. The multiplication speeds can be very slow to very fast depending on the exact hardware implementation used and the hardware constraints imposed.

The Am25LS14 can be used to perform multiplication of 2's complement numbers with a minimum of hardware. The new Am25LS14 provides the capability to perform very high speed direct hardware multiplications and is especially suited for real-time digital processing applications. This device will find applications in minicomputers, recursive or non-recursive digital filters, Fast Fourier Transform processors, adaptive digital integrators and many other digital implementations of special arithmetic algorithms.

MULTIPLICATION DEFINITION

According to Webster's Dictionary, multiplication is "a mathematical operation that at its simplest is an abbreviated process of adding an integer to itself a specified number of times and that is extended to other numbers in accordance with laws that are valid for integers." This definition is particularly appropriate for binary numbers in that all hardware binary multiplication schemes make an "add" or "no-add" decision and maintain the "weighting" rules of binary numbers. The two numbers involved in the operation are usually called the multiplicand (the number to be multiplied) and the multiplier

(the number that multiplies) with the result being called the product (later in this application note the partial products or partial sums will be important).

Binary multiplication is performed as in the following four digit example. The terms X and Y are:

$$X = x_0(2^0) + x_1(2^1) + x_2(2^2) + x_3(2^3)$$

$$X = x_0(1) + x_1(2) + x_2(4) + x_3(8)$$

$$Y = y_0(1) + y_1(2) + y_2(4) + y_3(8)$$

where x_i and y_i can assume a "0" or "1" value for $i = 0, 1, 2$ or 3 .

If X is the multiplicand and Y is the multiplier, the product S of X·Y is

$$\begin{aligned} S = X \cdot Y = & y_0(1) [x_0(1) + x_1(2) + x_2(4) + x_3(8)] \\ & + y_1(2) [x_0(1) + x_1(2) + x_2(4) + x_3(8)] \\ & + y_2(4) [x_0(1) + x_1(2) + x_2(4) + x_3(8)] \\ & + y_3(8) [x_0(1) + x_1(2) + x_2(4) + x_3(8)] \end{aligned}$$

In the above example, it can be seen that three additions are required to generate the product S of X·Y; the first two of these are usually called partial products or partial sums. In order to examine the weighting of the binary numbers in the above example, the complete partial product solution is shown in Figure 1 and the weights of the x terms and y terms have been combined.

Multiplicand	$x_3(8)$	+	$x_2(4)$	+	$x_1(2)$	+	$x_0(1)$	
Multiplier	$y_3(8)$	+	$y_2(4)$	+	$y_1(2)$	+	$y_0(1)$	
	$x_3y_0(8)$	+	$x_2y_0(4)$	+	$x_1y_0(2)$	+	$x_0y_0(1)$	
$x_3y_1(16)$	+	$x_2y_1(8)$	+	$x_1y_1(4)$	+	$x_0y_1(2)$		
Carry (32)	+	$Ps_4(16)$	+	$Ps_3(8)$	+	$Ps_2(4)$	+	$Ps_1(2) + Ps_0(1)$
$x_3y_2(32)$	+	$x_2y_2(16)$	+	$x_1y_2(8)$	+	$x_0y_2(4)$		
Carry (64)	+	$Ps_5(32)$	+	$Ps_4(16)$	+	$Ps_3(8)$	+	$Ps_2(4) + Ps_1(2) + Ps_0(1)$
$x_3y_3(64)$	+	$x_2y_3(32)$	+	$x_1y_3(16)$	+	$x_0y_3(8)$		
$s_7(128) + s_6(64)$	+	$s_5(32)$	+	$s_4(16)$	+	$s_3(8)$	+	$s_2(4) + s_1(2) + s_0(1)$

Figure 1. Multiplication of Two Unsigned 4-bit Numbers X and Y.

Understanding Booth's Algorithm

The $s_7(128)$ term represents the carry out of the final summation. As is seen, the multiplication of two 4-bit unsigned words results in an 8-bit product. This can be extended to a general statement; that is, the multiplication of a m -bit unsigned number with a n -bit unsigned number gives a $m + n$ bit resultant unsigned product. This number may be truncated of course and rules will be given later for determining the resulting accuracy when the hardware is being reduced.

It should be recognized that the product terms associated with y_0 and y_1 can be added in one adder and the product terms associated with y_2 and y_3 can be added in a second adder at the same time; thereby giving two partial products after one adder propagation delay time. These two partial sums can then be added in a third adder to give the resultant product of the multiplication.

One technique for reducing multiplication time that is presently being used in serial and serial-parallel multipliers is to ignore addition when the multiplier bit is a logic "0." When this is done the number of terms to be added is equal to the number of 1's in the multiplier word. This method can be extended in such a way that strings of 1's can also be ignored—this leads to an important new technique for performing high speed multiplication. This technique will be discussed in greater detail later.

Two's Complement				Decimal Number
Sign bit	2^3	2^2	2^1	
-8	4	2	1	
0	1	1	1	+7
0	1	1	0	+6
0	1	0	1	+5
0	1	0	0	+4
0	0	1	1	+3
0	0	1	0	+2
0	0	0	1	+1
0	0	0	0	0
1	1	1	1	-1
1	1	1	0	-2
1	1	0	1	-3
1	1	0	0	-4
1	0	1	1	-5
1	0	1	0	-6
1	0	0	1	-7
1	0	0	0	-8

Figure 2. Full Definition of a 4-bit Two's Complement Binary Number.

TWO'S COMPLEMENT NOTATION

This section is presented as a quick review of the two's complement numbering system and is intended to give insight for the designer not familiar with two's complement notation. The two's complement numbering system is a technique for describing positive and negative numbers in a convenient notation. When contrasted with other numbering systems such as sign-magnitude and one's complement, it has the advantage of only having one representation for the number "zero." Also, two's complement numbers can be added or subtracted without concern for the sign of each number as the result will be correct in two's complement notation.

In 2's complement notation, the sign bit is a logical "0" for positive numbers and a logical "1" for negative numbers. Four bits may be used to represent the numbers +7 to -8 as shown in Figure 2. Notice that the sign bit does carry magnitude information that has a negative value.

From this example, it is readily apparent that the magnitude of the negative numbers is not represented by its associated magnitude bits if the sign bit is ignored as is the case for the positive numbers. One way to find the absolute magnitude of a negative 2's complement number is to invert all bits and add plus binary one as in the example below:

```

1011  Negative 2's complement number
0100  Inverted
+ 0001  One Added
-----
0101  Result
    
```

From this example, it is seen that the magnitude of this negative numbers is five.

Likewise, to form a negative 2's complement number, the positive representation is taken, inverted, and plus binary one is added as shown.

```

Positive number +3
Binary representation      0011
Inverted                   1100
One added                  + 0001
-----
Minus three in two's complement  1101
    
```

The advantage of two's complement in many computers and digital processors is that addition and subtraction can be performed without regard to whether the numbers being added or subtracted are positive or negative. Examples of addition are shown in Figure 3. Note that overflows are discarded.

0001 +1	0001 +1	1110 -2
0101 +5	1111 -1	0110 +6
0110 +6	(1)0000 0	(1)0100 +4
0110 +6	1010 -6	1110 -2
1110 -2	0011 +3	1101 -3
(1)0100 +4	1101 -3	(1)1011 -5

Figure 3. Examples of Two's Complement Addition.

Subtraction is much like addition except that the number being subtracted (subtrahend) must be inverted and have one added to its value. It is then added to the minuend. This addition of +1 represents no problem in the hardware because the carry in (c_n) of the least significant adder can be used for this purpose — not an additional adder. Figure 4 shows examples of subtraction.

Minuend	0001 +1	1110 -2	1110 -2	1010 -6
Subtrahend	0101 +5	0110 +6	1101 -3	1101 -3
Minuend	0001	1110	1110	1010
Inverted Subtrahend	1010	1001	0010	0010
Add	1011	0111	0000	1100
Add One	0001	0001	0001	0001
Result (Binary)	1100	1000	0001	1101
Result (Decimal)	-4	-8	+1	-3

Figure 4. Examples of Two's Complement Subtraction.

From these examples, one might conclude that multiplication is simply the product of one 2's complement number with the other. Unfortunately, this is not correct for negative numbers. One obvious technique for multiplication in which negative numbers are represented by 2's complements is to determine the signs and magnitudes of the operands, multiply the magnitudes, and then if the result is negative, cast the result into 2's complement form. It seems preferable, however, to devise a scheme for multiplying such numbers more simply. Booth's method will be considered for this purpose.

BOOTH'S ALGORITHM

In the usual methods of digital multiplication, the multiplier digits are examined in turn and when the multiplier digit is a logical "1," the multiplicand is added to the running partial sum in the appropriate weight. For each multiplier digit, there is a relative one-digit shift between the multiplicand and partial sum whether there has been an addition or not. Booth's algorithm provides a tool whereby more than one shift at a time may be made, depending on the grouping of strings of logic 1's or logic 0's. This multiple shifting ability may be used to "speed up" the multiplication process.

Ordinary multiplication (disregarding signed numbers) can be performed by summing a series of partial products, each of which is one bit of the multiplier word, Y, times the entire multiplicand word, X, times the weight of the Y multiplier bit. That is,

$$\pi = \sum_{i=0}^{n-1} y_i \cdot X \cdot 2^i$$

where n = number of bits in Y

This method, usually designated "add and shift", is simply performed by ANDing the i-th multiplier bit, y_i , with the X value giving a result of X or 0, and then adding this result (X or 0) to the present partial product to generate a new partial product. The new partial product is then shifted one place toward the LSB. This divides it by 2 or, effectively, multiplies X by 2 relative to the partial product. The process

is then repeated for the next more significant bit of Y. This algorithm will work for 2's complement values of Y if for the most significant bit of Y, the sign bit, a subtraction rather than addition is performed. This results because the MSB of a 2's complement number effectively carries a negative rather than positive weight as shown in the following Y definition.

$$Y = -y_{n-1} (2^{n-1}) + y_{n-2} (2^{n-2}) + y_{n-3} (2^{n-3}) + \dots + y_0 (2^0)$$

Booth's algorithm is a multiplication technique which can reduce the number of operations required for multiplication. It operates on the fact that a string of 0's in the multiplier requires no additions but just shifting, and a string of 1's in the multiplier running from bit weight 2^r to weight 2^s can be treated as $2^{s+1} - 2^r$. For example, if $Y = 001110$ (LSB on right), then $r = 1$ and $s = 3$ and $2^4 - 2^1 = 14$. While the add and shift algorithm for this example requires three additions (if additions are ignored for $Y_i = 0$), Booth's algorithm requires only two operations. These are an addition at weight 2^{s+1} and a subtraction at weight 2^r . The algorithm can be verbally stated as follows:

- Examine the multiplier bit by bit beginning with the least significant bit and shifting the partial product relative to the multiplicand as each bit is examined.
- Subtract the multiplicand from the partial product when you find the first 1 in a string of 1's, add the multiplicand to the partial product when you find the first 0 in a string of 0's and do nothing when the bit is identical to the previous multiplier bit.

The significant features of this algorithm are that:

1. It can require n operations (compare, add/subtract, shift) for an n bit multiplier (of alternating 0's and 1's) but it usually requires fewer of these and the remainder are of the type compare, shift operations.
2. It works for X in 2's complement because addition and subtraction logic are identical for unsigned and 2's complement numbers.
3. It works for Y in 2's complement directly, because if Y ends in a string of 1's, the last operation will be a subtraction at the appropriate weight.

The basic algorithm as developed by Booth is as follows: y_i is the i-th most significant bit of an n-bit multiplier representation. y_{-1} is zero. y_0 is the least significant bit. y_{n-1} is the sign bit. X is the multiplicand.

Starting with $i = 0$, y_i and y_{i-1} are compared:

- 1.) If $y_i = y_{i-1}$; add 0X.
- 2.) If $y_i = 1$ and $y_{i-1} = 0$; subtract 1X (the multiplicand) from the partial product. (Add the 2's complement).
- 3.) If $y_i = 0$ and $y_{i-1} = 1$; add 1X to the partial product.

Two examples of this rules are shown in Figure 5.

Understanding Booth's Algorithm

Example 1:

$$\begin{array}{r} 1\ 0\ 1\ 1\ 1 = -9 \\ 0\ 1\ 0\ 1\ 1\ (0) = +11 \\ \hline 0\ 0\ 0\ 0\ 0\ 1\ 0\ 0\ 1 \quad y_0 = 1 \quad y_{-1} = 0 \\ 0\ 0\ 0\ 0\ 0\ 0\ 0\ 0 \quad y_1 = 1 \quad y_0 = 1 \\ 1\ 1\ 1\ 0\ 1\ 1\ 1 \quad y_2 = 0 \quad y_1 = 1 \\ 0\ 0\ 1\ 0\ 0\ 1 \quad y_3 = 1 \quad y_2 = 0 \\ 1\ 0\ 1\ 1\ 1 \quad y_4 = 0 \quad y_3 = 1 \\ \hline (1)\ 1\ 1\ 0\ 0\ 1\ 1\ 1\ 0\ 1 = -99 \end{array}$$

Example 2:

$$\begin{array}{r} 1\ 1\ 0\ 1\ 1 = -5 \\ 1\ 1\ 0\ 0\ 1\ (0) = -7 \\ \hline 0\ 0\ 0\ 0\ 0\ 0\ 1\ 0\ 1 \quad y_0 = 1 \quad y_{-1} = 0 \\ 1\ 1\ 1\ 1\ 1\ 0\ 1\ 1 \quad y_1 = 0 \quad y_0 = 1 \\ 0\ 0\ 0\ 0\ 0\ 0\ 0 \quad y_2 = 0 \quad y_1 = 0 \\ 0\ 0\ 0\ 1\ 0\ 1 \quad y_3 = 1 \quad y_2 = 0 \\ 0\ 0\ 0\ 0\ 0 \quad y_4 = 1 \quad y_3 = 1 \\ \hline (1)\ 0\ 0\ 0\ 1\ 0\ 0\ 0\ 1\ 1 = +35 \end{array}$$

Figure 5. Examples of Booth's Algorithm for Two's Complement Multiplication.

Based on these rules as developed by Booth, it is a straight forward process to make a table of desired action for each of the four possible two-bit combinations under inspection. This is shown below. K is the partial product before this level of the algorithm and is zero initially.

Table of Operation for Booth's Algorithm

y_{i-1}	y_i	Function	Partial Product
0	0	Do nothing	$K + 0$
1	0	Add X	$K + X$
0	1	Subtract X	$K - X$
1	1	Do nothing	$K + 0 = K - 0$

Note that when $y_i = 0$ and add is required and when $y_i = 1$ a subtract is used. Also, when $y_i \oplus y_{i-1} = 1$ the multiplicand is added (or subtracted) from the running partial product K and when $y_i \oplus y_{i-1} = 0$, zero is used.

INTEGER MULTIPLICATION

We can multiply 2's complement numbers in either integer or fractional form. The primary difference is in the thought process of the designer. When the binary patterns are treated as integers, the 2's complement numbers can be represented as

$$\begin{aligned} X &= x - x_s 2^{n-1} \\ Y &= y - y_s 2^{m-1} \end{aligned}$$

where

- x_s = sign bit of X (one or zero)
- y_s = sign bit of Y (one or zero)
- x = magnitude bits of X (less sign)
- y = magnitude bits of Y (less sign)
- n = number of bits in X word
- m = number of bits in Y word

For example, if six bits are assumed for X, $n = 6$ and the sign bit has a weight of $-2^{6-1} = -2^5 = -32$. The other magnitude bits have their normal weight and since there are five other magnitude bits, they are $2^0, 2^1, 2^2, 2^3$, and 2^4 . Thus, 2's complement integer numbers for $n = 6$ bits are as shown below:

Integer Decimal Number Equivalent	Magnitude bits					
	-2^5 Sign	2^4	2^3	2^2	2^1	2^0
14	0	0	1	1	1	0
31	0	1	1	1	1	1
0	0	0	0	0	0	0
-7	1	1	1	0	0	1
-25	1	0	0	1	1	1
-32	1	0	0	0	0	0

When the product of X and Y is considered, the following equation results:

$$S = XY = x_s y_s 2^{m+n-2} - x y_s 2^{m-1} - y x_s 2^{n-1} + xy$$

The 2's complement product requires $m + n$ bits in order to represent all possibilities. Note that there is only one condition where the $m + n$ bits are required; that condition being:

$$X = -2^{n-1} \text{ and } Y = -2^{m-1}$$

This condition gives $S = XY = 2^{m+n-2}$ which requires $m + n$ digits in a 2's complement signed integer number.

Consider $n = 6$ and $m = 4$, then x_s has weight -32 and y_s has weight -8 . For $X = -32$ and $Y = -8$, the product XY is $+256$. The 2's complement representation is 0100000000 . Ten bits are required to properly represent the 2's complement number. All other combinations of values for X and Y require only $m + n - 1$ bits to represent the 2's complement number. For $n = 6$ and $m = 4$ in this case, the ninth bit represents the product sign. Consider $(+7) \times (-31)$ is equal to -217 or 100100111 . Notice that 1100100111 , the ten bit 2's complement representation is identical in value.

The general requirement for the product solution of XY is:

$$S = XY = s - s_s 2^{m+n-1}$$

and all binary operations must be carried through $m + n$ bits in the product solution unless a simplification is assumed.

FRACTIONAL MULTIPLICATION

Fractional multiplication is identical with integer multiplication but the notation is changed. The fractional number range is usually limited to $-1 \leq X \leq 1 - 2^{-(n-1)}$.

The fractional 2's complement binary numbers can be represented as:

$$X = x \cdot 2^{-(n-1)} - x_s$$

$$Y = y \cdot 2^{-(m-1)} - y_s$$

$$K = k \cdot 2^{-(p-1)} - k_s$$

where the notation is as with integer arithmetic. The sign bit now has a weight of $-2^0 = -1$ and the other magnitude bits have their normal fractional weight.

Two's complement numbers for $n = 6$ are as shown below.

Fractional Equivalent	-2^0	2^{-1}	2^{-2}	2^{-3}	2^{-4}	2^{-5}
	-1	1/2	1/4	1/8	1/16	1/32
$14/32 = 7/16$	0	0	1	1	1	0
$31/32$	0	1	1	1	1	1
0	0	0	0	0	0	0
$-7/32$	1	1	1	0	0	1
$-25/32$	1	0	0	1	1	1
$-32/32 = -1$	1	0	0	0	0	0

The notation difference in the fractional representation is that all the integer representations have been divided by $2^{(n-1)}$.

The fractional product XY is

$$S = XY = x_s y_s - x_s y \cdot 2^{-(m-1)} - y_s x \cdot 2^{-(n-1)} + xy \cdot 2^{-(m+n-2)}$$

Again, $m+n$ bits are required to cover all possible combinations. Note that $X = -1$ and $Y = -1$ results in $XY = +1$ which is beyond the normal range. In order to cover this possibility, the sign bit should be given a weight of -2 (instead of -1); the next most significant bit is weight $+1$, the next is $+1/2$, and so forth. If the -1 times -1 possibility is excluded only $m+n-1$ bits are required.

This general equation requires the sign bit to have a weight of -2 and all arithmetic to be carried to $m+n$ bits to represent the two's complement solution.

A HIGH-SPEED SERIAL/PARALLEL MULTIPLIER

THE Am25LS14*

By John Mick, John Springer and Clive Ghest

INTRODUCTION

The Am25LS14 is a complete 8-bit Serial/Parallel Multiplier fabricated as a single 16-pin LSI chip. The device accepts a parallel two's complement or unsigned multiplicand and multiplies it by any arbitrary length serial two's complement or unsigned multiplier. The resulting product is a correct and complete serial two's complement or unsigned product. The complete product of an 8 x 8 multiplication can be performed in 16 clock cycles. Any number of Am25LS14 devices can be cascaded with no additional logic, so that the parallel multiplicand can be easily expanded to any number of bits. Mixed signed (two's complement) and unsigned multiplication is possible, generating a product in signed two's-complement form.

MULTIPLIER CHARACTERISTICS

The requirements for a good general purpose IC multiplier for use in a wide range of commercial applications are as follows:

- It should be inexpensive
- It should be fast
- It should be easy to use
- It should be adaptable to any word length
- It should handle signed numbers in two's complement notation without correction.

The first two of these requirements tend to be incompatible and in the past have required two types of circuits: one which was designed to be as fast as possible and another which compromised speed for cost. The last two requirements limit the method used to perform the multiplication to an algorithm which works in two's complement notation and is the same for all bits, so that the "sign bit" is treated identically with the other bits.

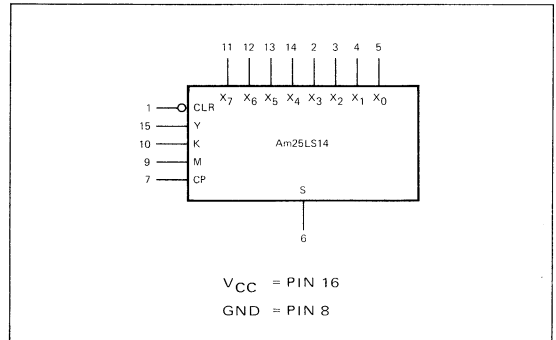


Figure 2. Logic Symbol for the Am25LS14 (16-Pin Device)

The Am25LS14 offers an optimum solution to these requirements. It operates by taking the whole multiplicand in parallel and utilizing a single bit at a time of the multiplier word to form partial products in an internal register. The output is a serial bit stream representing the product of the parallel multiplicand word and the serial multiplier word.

THE LOGIC FUNCTION

A simplified logic diagram of the Am25LS14 Serial/Parallel multiplier is shown in Figure 1 and the 16-pin logic symbol for the device is shown in Figure 2. The multiplier consists of four basic parts; a storage register used to hold the multiplicand word during the multiplication, the adder/subtractor logic containing both a partial product register and a carry/borrow register, a flip-flop and exclusive-NOR gate operating on the serial multiplier string presented at the Y input to provide a

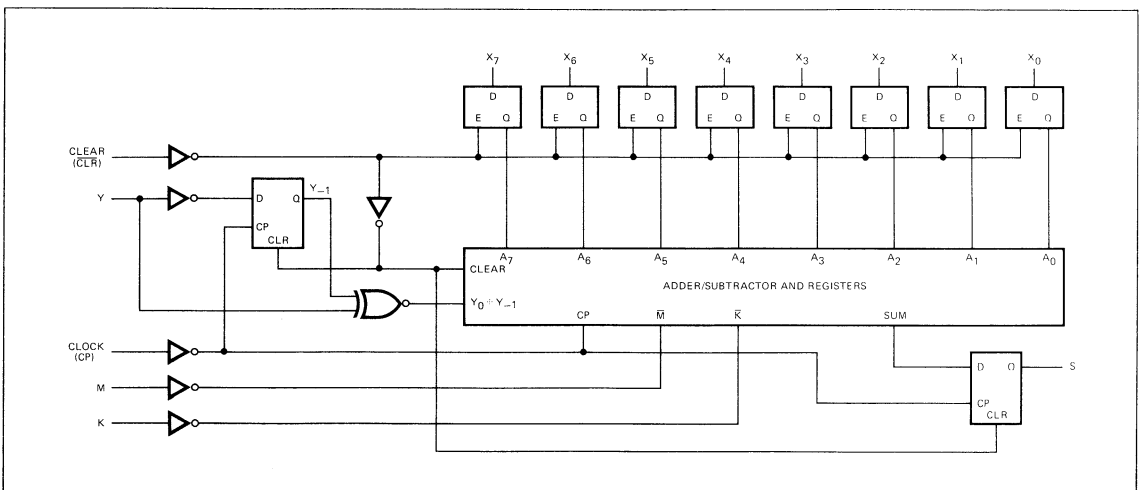


Figure 1. Functional Logic Diagram for the Am25LS14

*The Am25LS14 is manufactured under U. S. Patent No. 3,878,985 issued April 22, 1975.

control signal to the adder/subtractor logic, and a logic mode circuit to alter the multiplicand from two's complement to unsigned notation as controlled by the M input. The adder/subtractor logic and product and carry/borrow register is iterative; that is, it consists of eight identical cells with a small change in the eighth cell to efficiently incorporate the multiplicand word sign logic. For a detailed description of the logic design of the Serial/Parallel multiplier, refer to the application note "Mechanization of the Serial/Parallel Multiplier" by John R. Mick.

Prior to a multiplication, the internal multiplier sum and carry registers are reset by applying a LOW to the clear input. The 8-bit multiplicand data is applied to the X inputs and is latched into the multiplicand register as the clear input goes HIGH. This internal multiplicand storage is useful because the multiplicand need not be held constant during the multiplication allowing these inputs to be bus organized. The Serial/Parallel multiplier is now ready to receive the first least significant multiplier bit. The least significant bit of the multiplier word is presented at the Y serial input and when the clock changes from LOW to HIGH, the multiplier produces the first least significant product bit at the serial data output, S. In each succeeding clock period, the next more significant multiplier bit is presented at the Y input and the next more significant product bit is present at the S output. After 8 clock periods, the multiplier serial input string has been exhausted but the most significant half of the product is still in the internal registers of the Am25LS14 Serial/Parallel multiplier and must be clocked out. If the multiplier is an unsigned word, then during the extraction of the most significant half of the product, the multiplier Y input must be held at logic zero. If, however, the multiplier is a two's-complement signed word, then the most significant bit (sign bit) of the multiplier word must be repeated at the Y input until the complete product has been obtained. The multiplicand can be either an unsigned number or a two's-complement number depending upon the logic polarity of the mode input, M. This mode input should be held at a LOW logic level (ground) if the multiplicand is in two's-complement notation and the X₇ input is a two's complement sign bit, and it should be held at a HIGH logic level (pulled up through a register to V_{CC}) if the 8-bit multiplicand is unsigned (magnitude only number).

The K input is used for expansion purposes. To increase the length of the multiplicand word by using multiple devices, the S output of a higher order device is connected to the K input of the next lower order devices. The clear lines are connected together and the clock lines are connected together. All the mode inputs except the one on the most significant device are held at a HIGH logic level. Whether the multiplicand is signed or unsigned is determined only by the M input of the most significant device. A 24-bit by n-bit multiplier is shown in Figure 3. The K input is held LOW at the most significant device indicating a two's complement multiplicand. The multiplier input can be any length, with n + 24 clock periods required for the multiplication. The resulting product is n + 24 bits long.

If the multiplicand is not an even multiple of 8 bits, then for an unsigned multiplicand the remaining most significant multiplicand inputs are held LOW at logic zero, while for a two's-complement multiplicand, the remaining multiplicand inputs must be connected to the multiplicand sign bit so that the sign is extended and can be interpreted correctly. Figure 4 shows a 12 x n Serial/Parallel multiplier connection for a two's-complement signed multiplicand. The resulting product is n + 12 bits long and only n + 12 clock periods are required to generate the correct product.

The Function Table for the Am25LS14 multiplier operation is given in Figure 5. As shown, the K input is the sum expansion input and allows for the cascading of devices. The mode input, M, is used in conjunction with cascading to determine the most significant bit of the multiplicand and controls the multiplicand sign definition.

TIMING

Although the Serial/Parallel multiplier requires only m + n clock periods to produce a full length product, (where m is the multiplicand word length and n is the multiplier word length) a practical system may use two additional clock periods. The first additional clock period is used to reset the multiplier at the beginning of a multiplication by using the clear input. This is shown in the timing diagram of Figure 6. This clears the partial product register, the carry/borrow register and the

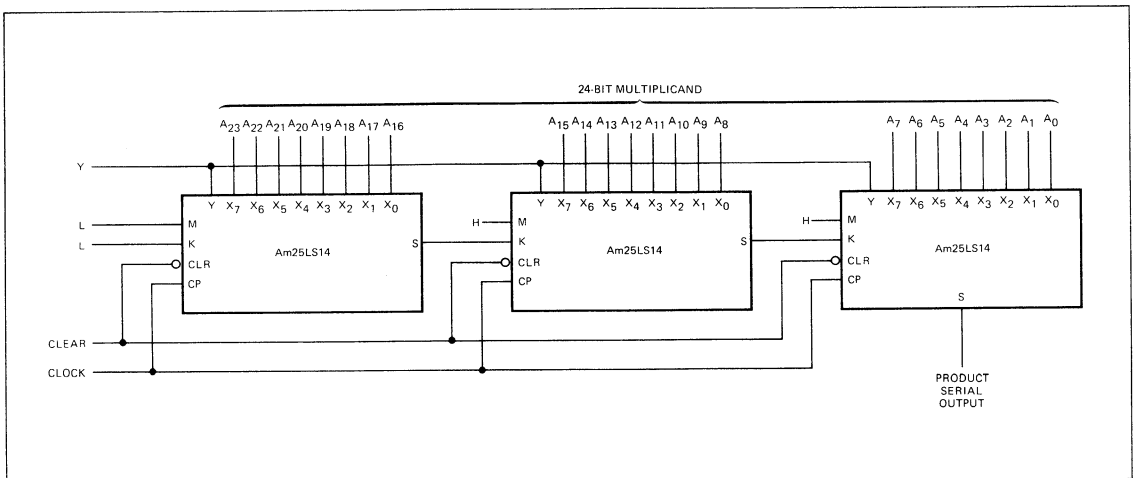


Figure 3. Three Am25LS14's Cascaded to Make a 1-Bit by 24-Bit Serial-Parallel Multiplier

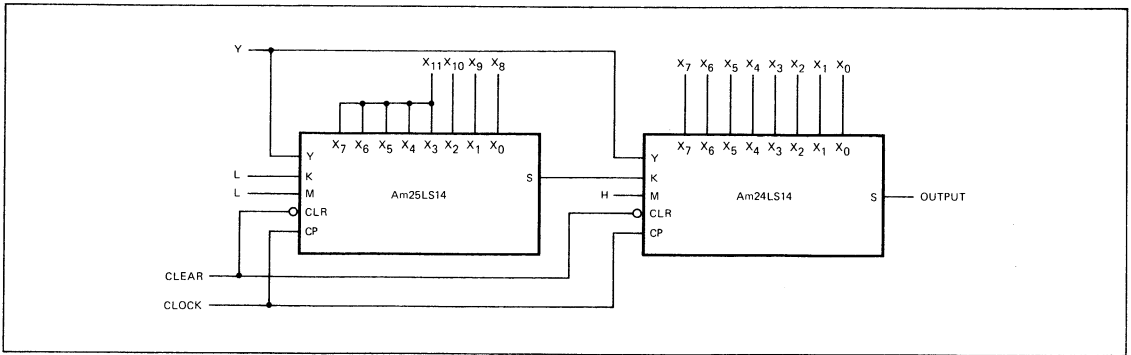


Figure 4. A 12-bit by N-bit Two's Complement Multiplier Using Two Am25LS14's

INPUTS						INTERNAL	OUTPUT	FUNCTION
CLR	CP	K	M	X _i	Y	Y ₋₁	S	
-	-	L	L	-	-	-	-	Most Significant Multiplier Device
-	-	CS	H	-	-	-	-	Devices Cascaded in Multiplier String
L	-	-	OP	-	-	L	L	Load New Multiplicand and Clear Internal Sum and Carry Registers
H	-	-	-	-	-	-	-	Device Enabled
H	↑	-	-	-	L	L	AR	Shift Sum Register
H	↑	-	-	-	L	H	AR	Add Multiplicand to Sum Register and Shift
H	↑	-	-	-	H	L	AR	Subtract Multiplicand from Sum Register and Shift
H	↑	-	-	-	H	H	AR	Shift Sum Register

H = HIGH
 L = LOW
 ↑ = LOW-to-HIGH transition
 CS = Connected to S output of higher order device
 OP = X_i latches open for new data (i = 0, 7)
 AR = Output as required per Booth's algorithm

Figure 5. Function Table Showing the Operation of the Am25LS14

control flip flop, and loads the new multiplicand into the X holding latch. At this same time, the multiplier word can be loaded into a Parallel-to-Serial converter (such as the Am25LS22) ready for presenting to the Serial/Parallel multiplier Y input. During the first time period after the clear

signal, the least significant bit of the multiplier is presented to the Y input of the Am25LS14 and in the next clock period the first bit of the product, S₀, is available at the S output of the device. For the next n-1 clock periods, the multiplier bits are presented one at a time to the multiplier Y input and the

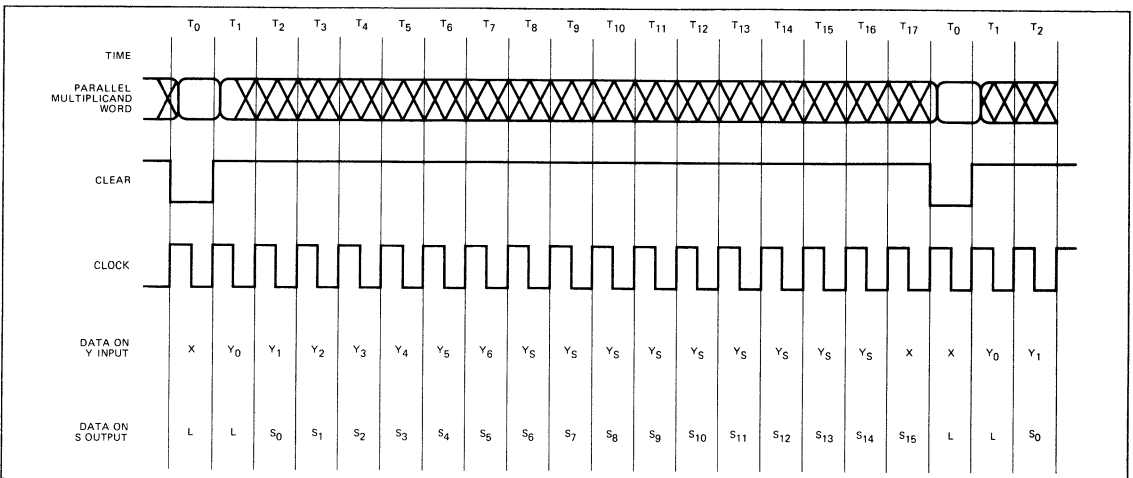


Figure 6. Timing Diagram Showing 18 Clock Cycle Operation of 8 x 8 Multiplication

product bits are available one at a time from the S output. For the remaining m clock periods, the Serial/Parallel multiplier requires that either the most significant bit of the multiplier word, Y , be repeated (two's complement operation) or a string of zeroes be applied (if the multiplier is to be treated as an unsigned number) to the Y input.

It is possible to perform an $m + n$ multiplication using only one additional clock cycle. This requires that the clear pulse is presented at the same time as Y_0 , the least significant Y multiplier bit. Since the minimum clear pulse width is 20ns and the clear recovery time is 18ns, the time duration must be at least 38ns minimum for this clock period. A timing diagram for this mode of operation is shown in Figure 7.

Many applications, especially when using two's complement operands, do not require a full $n + m$ bit product but only an $m + n - 1$ bit product. For example, if fractional operands in

the number range of -1 to $1 - 2^{-(n-1)}$ and -1 to $1 - 2^{-(m-1)}$ are assumed, only the case of -1 times -1 requires $m + n$ bits to represent the product. All other combinations can be represented correctly in two's complement notation by $m + n - 1$ bits. That is, when dealing with fractions, only one bit to the left of the binary point carrying a weight of -1 is required except for the one special case. This can be used to remove one additional clock cycle from the multiplication process as shown in Figure 8. The same reasoning applies to integer representations where the largest negative numbers are $-2^{(m-1)}$ and $-2^{(n-1)}$. Only $m + n$ bits are required to handle the case of $(-2^{(m-1)}) \cdot (-2^{(n-1)}) = (+2^n)$ in two's complement. All other products for a 3-bit and 4-bit multiplicand and multiplier can be represented correctly in two's complement form with a 6-bit representation.

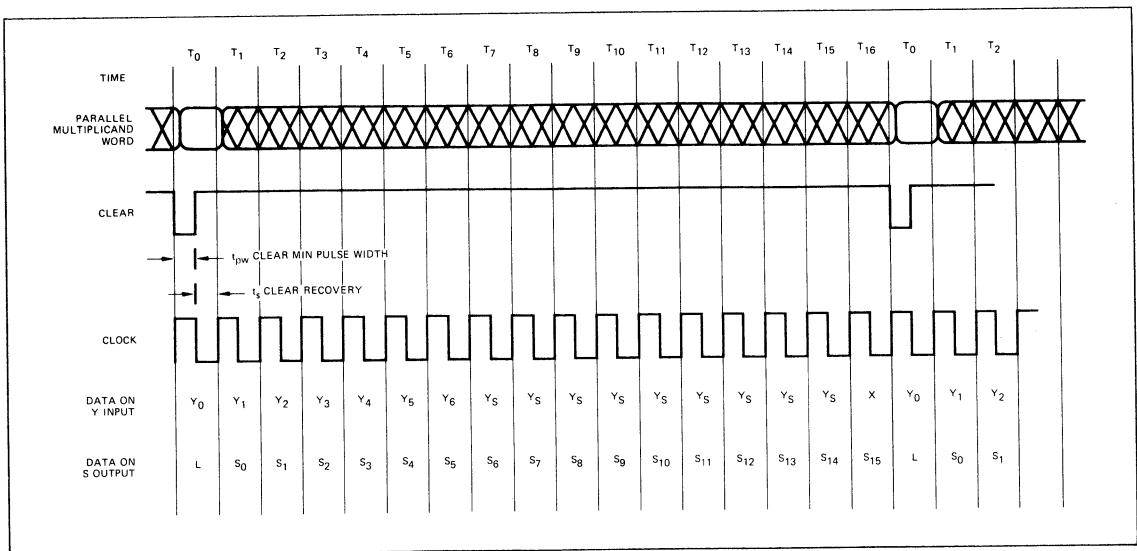


Figure 7. Timing Diagram Showing 17 Clock Cycle Operation of 8 x 8 Multiplication

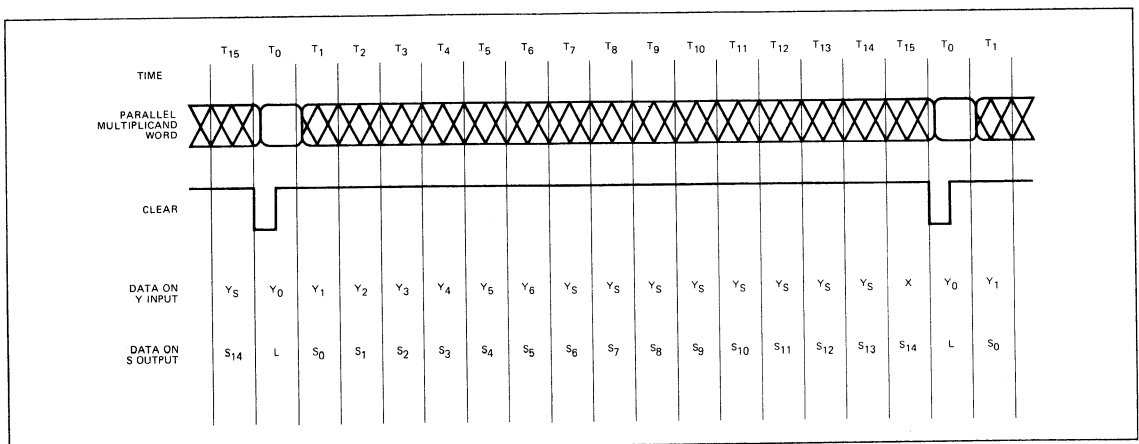


Figure 8. Timing Diagram Showing 16 Clock Cycle Operation for an 8 x 8 Multiplication (Assumes a 15-Bit Product Representation)

5

ROUNDING AND TRUNCATION

Truncation is performed in the Am25LS14 by ignoring the appropriate number of least significant bits (LSB's). Unfortunately, no clock cycles can be saved when truncating because the product is being developed LSB first. Therefore, the truncated bits are the first bits out of the Am25LS14 multiplier. The subsystem must be clocked the total number of times $(m + n)$ to develop the two's complement product. This does have the advantage of saving register bits to hold the product from the device.

To date, the recommended method of rounding is to use one-fourth of an Am25LS15 to perform rounding. This technique involves adding a one at the bit prior to the LSB of the final product using one input of the Am25LS15. The product from the multiplier is connected to the other input. This does require one extra clock cycle to implement rounding. This technique works for any combination of multiplicand bits, multiplier bits and desired product bits.

APPLICATIONS

Eight-Bit by Eight-Bit Multiplier

A circuit which generates a 16-bit product from an 8-bit by 8-bit multiplication is depicted in Figure 9. This sub-system consists of one Am25LS14 serial/parallel multiplier and two Am25LS22 8-bit registers. This configuration accepts an 8-bit multiplicand and an 8-bit multiplier from an 8-bit data bus. It will return a 16-bit product (8-bit upper byte and 8-bit lower byte) using the same 8-bit bus.

The Am25LS22 is an 8-bit register designed for performing various functions with the Am25LS14. It can be used to hold the multiplier word initially, perform the sign-extend function and then hold part of the product. It has separate serial input/output capability as well as shared parallel input/outputs.

The timing sequence for controlling this circuit is shown in Figure 10. Twenty-two clock cycles are used in this example to fully load, multiply and unload the multiplier subsystem. Thus, such an arrangement can be used with any of the popular 8-bit MOS microprocessors such as the 8080, 6800, 2650, F8 and others. This allows the multiplication to be performed outside of the MOS microprocessor with about two to three orders of magnitude improvement in speed.

Referring to the timing sequence of Figure 10, the multiplier word is loaded into the Am25LS22 register at time T_1 and the multiplicand word is loaded in the Am25LS14 latches during time T_1 . The multiplicand and multiplier words must be loaded in this order since there is no hold function on the Am25LS14 multiplier.

During time T_2 through T_{10} , the least significant product bits are generated and clocked into holding register B. Meanwhile the multiplier sign bit is being extended in Register A. The sign extend is performed only for the eight clock cycles T_2 through T_9 . During time T_{11} through T_{18} , the most significant 8-bits of the product are developed in the Am25LS14 multiplier. T_8 is used to load the product sign bit from the multiplier into the Am25LS22 B register. During the time T_1 through T_8 , the least significant half of the product is transferred from register B to register A. The remaining two clock cycles, T_{19} and T_{20} are used to unload the product upper and lower byte back onto the 8-bit data bus.

The control signals required for this multiplier are shown in Figures 9 and 10. Notice that the clear input to the Am25LS14 and the Serial/Parallel (S/P) input to the Am25LS22 can be connected together with the appropriate don't cares eliminated. Other control signals to the Am25LS22 include the register enable (RE), sign extend (SE), and the three-state control (OE). These signals can be generated using a counter and combinatorial logic gates or a counter and small PROM.

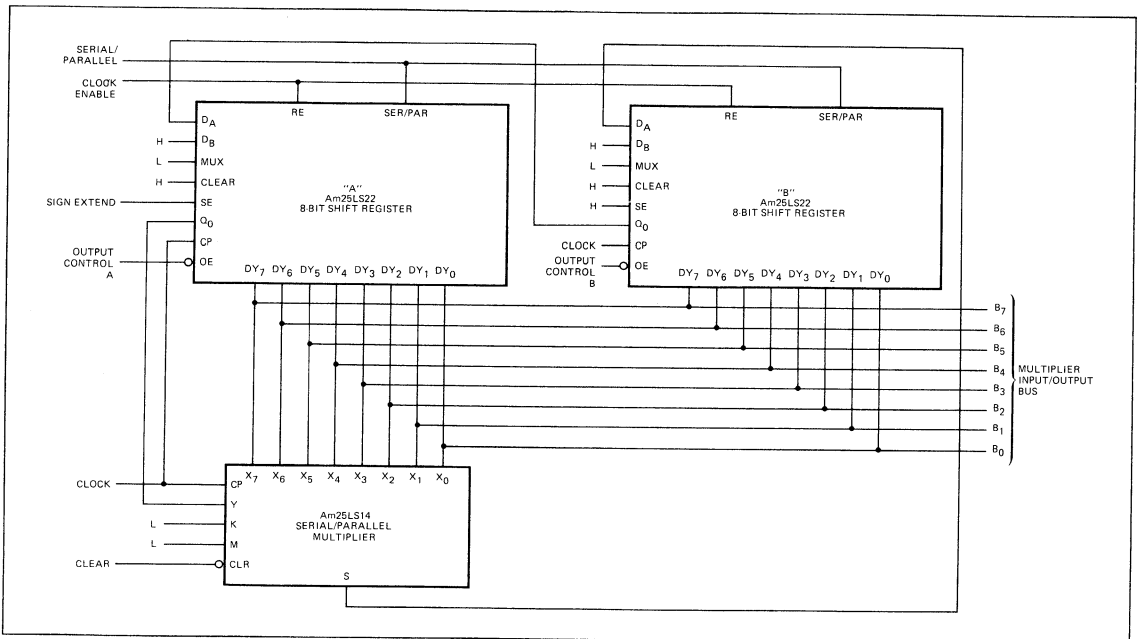


Figure 9. An 8-Bit by 8-Bit Multiplier with a Full 16-Bit Product Store. The Inputs and Outputs are Bus Organized on an 8-Bit Bus

TIME	I/O BUS	Am25LS14			Am25LS22's					FUNCTION
		Y	CLR	S	S/P	RE	SE	OE	A	
T ₀	Multiplier	X	X	X	L	L	X	H	H	Load Multiplier (Y) Load Multiplicand (X)
T ₁	Multiplicand	X	L	X	X	H	X	H	H	
T ₂	X	Y ₀	H	L	H	L	L	H	H	Present Y _i to multiplier. Read S _i into Register B. Extend Y sign.
T ₃	X	Y ₁	H	S ₀	H	L	L	H	H	
T ₄	X	Y ₂	H	S ₁	H	L	L	H	H	
T ₅	X	Y ₃	H	S ₂	H	L	L	H	H	
T ₆	X	Y ₄	H	S ₃	H	L	L	H	H	
T ₇	X	Y ₅	H	S ₄	H	L	L	H	H	
T ₈	X	Y ₆	H	S ₅	H	L	L	H	H	
T ₉	X	Y _S	H	S ₆	H	L	L	H	H	
T ₁₀	X	Y _S	H	S ₇	H	L	H	H	H	Continue Multiplication using Y _S in register. Load least significant part of product into Register A and most significant in Register B.
T ₁₁	X	Y _S	H	S ₈	H	L	H	H	H	
T ₁₂	X	Y _S	H	S ₉	H	L	H	H	H	
T ₁₃	X	Y _S	H	S ₁₀	H	L	H	H	H	
T ₁₄	X	Y _S	H	S ₁₁	H	L	H	H	H	
T ₁₅	X	Y _S	H	S ₁₂	H	L	H	H	H	
T ₁₆	X	Y _S	H	S ₁₃	H	L	H	H	H	
T ₁₇	X	Y _S	H	S ₁₄	H	L	H	H	H	
T ₁₈	X	X	H	S ₁₅	H	L	H	H	H	Load MSB into Register.
T ₁₉	Product Lower Byte	X	X	X	X	H	X	L	H	Unload product Lower byte onto bus.
T ₂₀	Product Upper Byte	X	X	X	X	H	X	H	L	Unload product Upper byte onto bus.

H = HIGH L = LOW X = Don't Care

Figure 10. Timing Sequence for an 8 x 8 Multiplier with Full 16-Bit Product Register

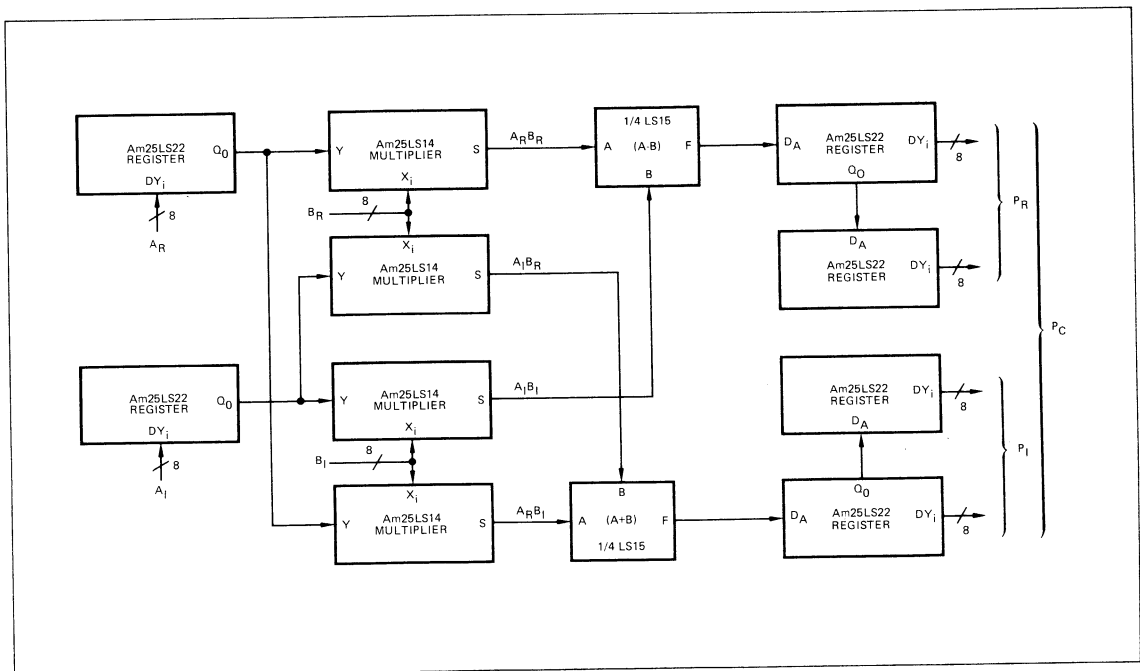


Figure 11. Complex Arithmetic Multiply $P_C = (A_R B_R - A_I B_I) + j(A_R B_I + A_I B_R)$

COMPLEX ARITHMETIC MULTIPLIER

The Am25LS14 serial/parallel multiplier, the Am25LS15 adder/subtractor, and the Am25LS22 eight-bit register can be used to perform rapid multiplication in complex arithmetic processors. In complex arithmetic notation, each variable is assumed to have a real part and an imaginary part. Thus, complex variables A_C and B_C may be represented as:

$$A_C = A_R + jA_I$$

$$B_C = B_R + jB_I$$

The product of A_C and B_C is, of course, complex product P_C where:

$$P_C = P_R + jP_I = A_C B_C$$

$$P_C = (A_R + jA_I) (B_R + jB_I)$$

$$P_C = (A_R B_R - A_I B_I) + j(A_R B_I + A_I B_R)$$

From this discussion, the real and imaginary values of the product P_C are readily identified. These are:

$$P_R = A_R B_R - A_I B_I$$

$$P_I = A_R B_I + A_I B_R$$

The circuitry required to implement this complex multiplier is shown in Figure 11. In this example, the real and imaginary values of the A_C variable are loaded into the two Am25LS22 registers. The real and imaginary values of the B_C variable are

loaded into the latches of the Am25LS14. This loading of the data could be performed simultaneously using all four inputs A_R , A_I , B_R and B_I or it could be performed sequentially using a pair of inputs or a single input at a time.

Once the incoming A_C and B_C data have been loaded, the devices are clocked such that the four intermediate products are formed as shown in Figure 11. Then, two of the four adder/subtractors in the Am25LS15 are used to complete the generation of real product term P_R and the imaginary product term P_I .

These product terms P_R and P_I can be loaded into four additional Am25LS22 registers to hold the double length product terms P_R and P_I (assume least significant bit truncation). After the complex multiplication has been completed, the P_R and P_I variables can be returned to the processor, memory or other destination by using the parallel bus outputs of the Am25LS22.

OTHER APPLICATIONS

Other examples of applications using the Am25LS14 as well as the Am25LS15 and Am25LS22 are shown in Figures 12 through 15. Each of these applications is intended to give the design engineer a new approach to solving numerical problems involving digital multiplication.

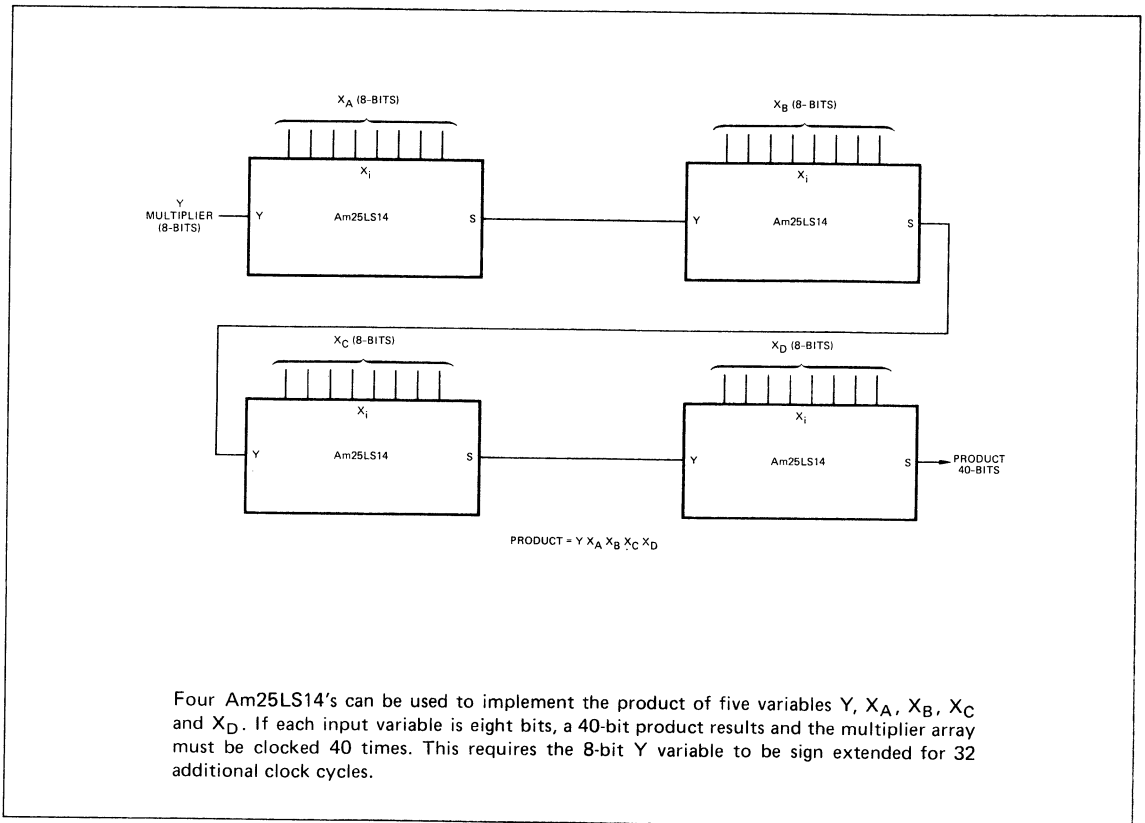


Figure 12. Multiple Operand Multiplications

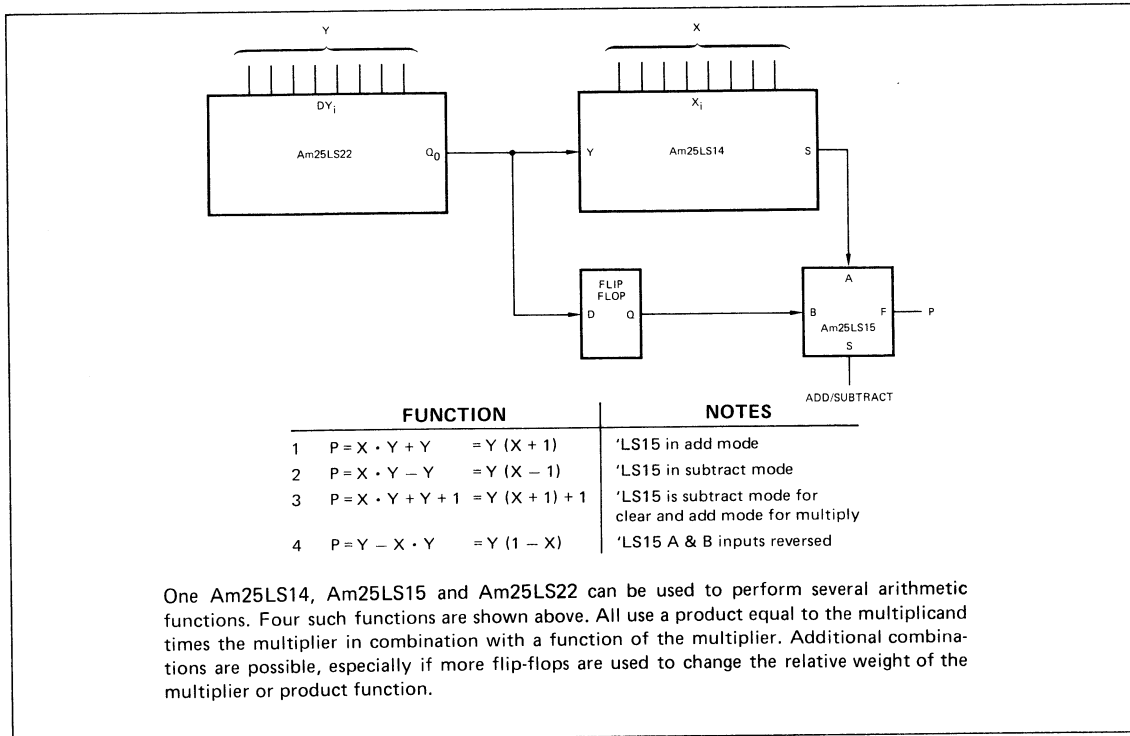


Figure 13.

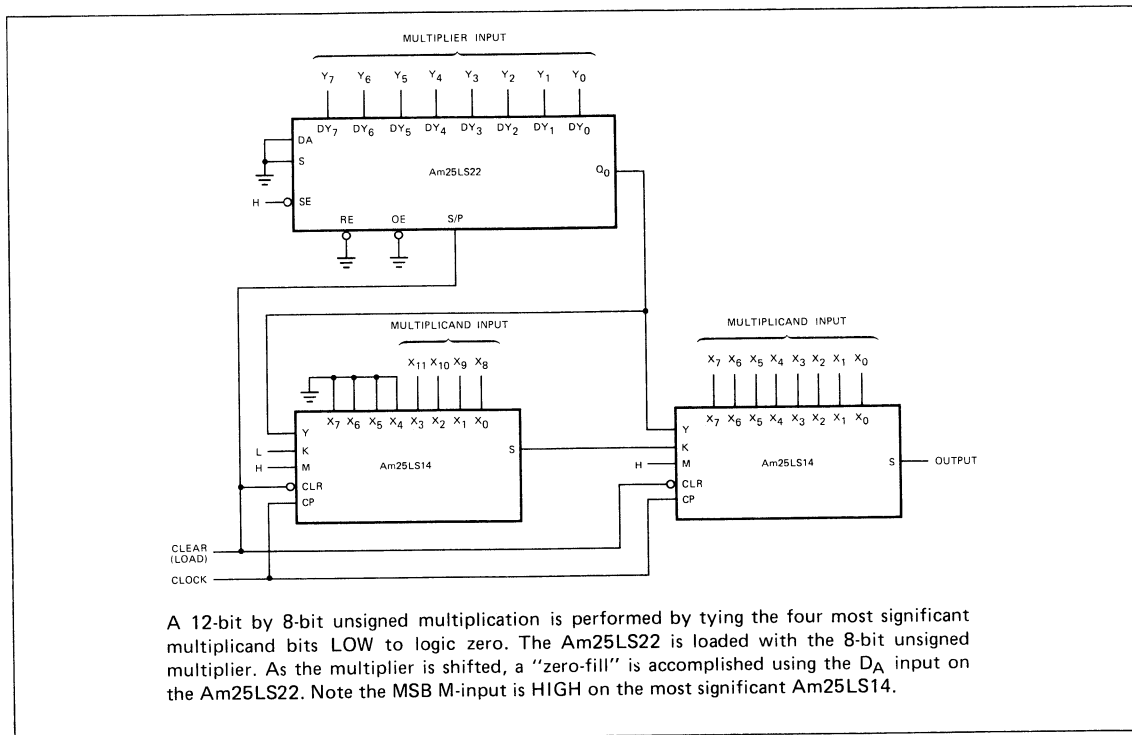
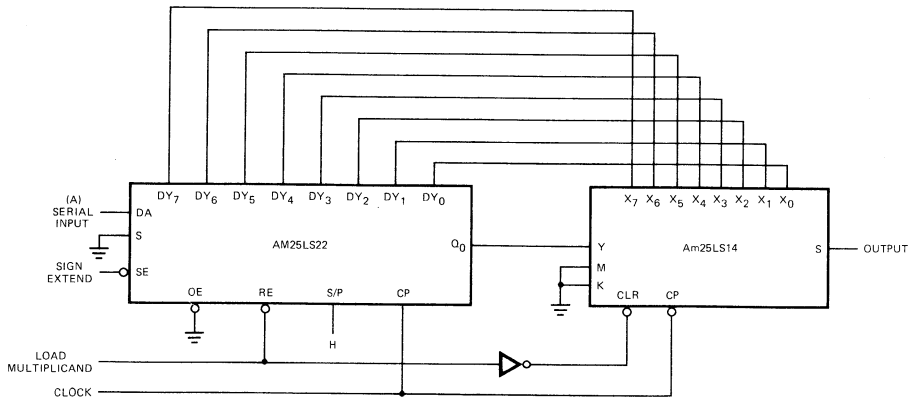


Figure 14.



One Am25LS14 and Am25LS22 can be used to perform the function A^2 on an input variable A. The 8-bit value for A is loaded into the Am25LS22 register in serial form using the D_A input. Once loaded, the A value can be transferred to the Am25LS14 multiplicand latches via the DY_i outputs. Then the product of $A \cdot A$ is formed resulting in A^2 at the Am25LS14 output.

Figure 15.

MECHANIZATION OF THE Am25LS14 SERIAL/PARALLEL MULTIPLIER

By John R. Mick

The Am25LS14 Serial/Parallel Multiplier uses Booth's algorithm to give the correct two's complement product without the need of post multiplication correction. The algorithm requires that two bits of the multiplier are examined at each time period. These bits are y_a , the multiplier bit at the present time t_a , and y_{a-1} , the multiplier bit at the previous time t_{a-1} . The assumption is made that at each time, t_a , it is the last multiplier bit in the word and, therefore, it carries a negative weight; if it is a logic one, a subtraction takes place at this weight. If this was not the last bit in the word, a correction takes place during the next time period. The logic, therefore, not only has to examine the multiplier bit y_a in the current time but also the previous y_{a-1} in order to discover whether a correction is necessary.

The algorithm is performing the function:

$$S = \sum_{a=0}^{n-1} \{ y_a (-2^a) + y_{a-1} (2^{a-1}) \}$$

where: S = the product $X \cdot Y$,

X = the multiplicand

y_a = the current multiplier bit

y_{a-1} = the previous multiplier bit

-2^a = two's complement weight of the current multiplier bit

$+2^{a-1}$ = two's complement weight of the previous multiplier bit

n = total number of bits in the multiplier

Obviously, if at t_a , y_a is a one and X is positive, then S is negative. If X is negative, then S is positive for $y_a = 1$ at $a = n-1$ which is exactly what is required at the last bit operation during a two's complement multiplication.

The four possibilities of $y_a y_{a-1}$ give the following requirements in order to satisfy Booth's algorithm.

$y_a y_{a-1}$	Function
0 0	No arithmetic operation. Shift partial product relative to multiplier.
0 1	Add multiplicand to partial product, S , and shift new partial product.
1 0	Subtract multiplicand from partial product, S , and shift new partial product.
1 1	No arithmetic operation (perform correction by executing both add and subtract of equation 1). Shift partial product relative to multiplier.

The last entry with $y_a y_{a-1} = 1, 1$ is made up of an addition and a subtraction of the multiplicand at weights offset by 2. This is used to perform the correction associated with the previous iteration where y_a was also a logic 1 and given nega-

tive weight. Since a shift has now taken place, the addition of $(X y_{a-1} 2^{a-1})$ cancels the previous subtraction of $-X y_a 2^a$ before the shift and has the effect of extending the sign of the running partial product.

IMPLEMENTING THE CARRY

The next consideration in the Am25LS14 Serial/Parallel Multiplier is the carry scheme to be used for the arithmetic section. Since an essential characteristic of the design is a very high processing rate, the carry scheme must have as few a number of gate delays as possible. There are many look-ahead carry schemes but they all suffer from two problems. The carry network becomes increasingly complex as the word length is increased and in any practical scheme, additional delay is incurred for longer word lengths. What is required is a method where the carry delay is short and independent of the word length of the multiplicand.

One method of obtaining this result is called a "stored carry adder" and is particularly suited to serial/parallel arithmetic. The concept is straightforward but is complicated in the Am25LS14 because not only are carries generated but also borrows. (It assists understanding if these borrows are treated as negative carries.) In the stored carry scheme, when an addition (or subtraction) takes place, instead of the carry (borrow) being presented to the next arithmetic stage so as to affect the next sum bit and be used to generate the carry at that stage for the next stage, the carry is stored in a flip-flop at the same stage and incorporated into the arithmetic at the next time iteration of the addition (subtraction).

A combinatorial design of an MSI Serial/Parallel Multiplier is shown in Figure 1. The inputs to the Am25LS181 adder/subtractor are the partial product and the multiplicand. The multiplicand is gated by a function of the $y_a y_{a-1}$ multiplier bits by using the mode control of the Am25LS181. The sum or new partial product out of the 'LS181 adder/subtractor is shifted one place down and stored in the next lower stage partial product register made up of the Am25LS174's. In each adder stage, the generated carry goes to the next higher adder stage internally.

The stored carry concept is shown in Figure 2. Here, the inputs to the full adder are the partial product, the multiplicand gated by the $y_a y_{a-1}$ and the previously stored carry generated at the same stage during the previous cycle. The outputs of the full adder are the sum which is stored in the sum partial product flip-flop at the next lower stage and the carry which is stored in the carry flip-flop at the same stage and is not shifted down. The stored carry concept uses an additional flip-flop per multiplicand bit compared to the standard MSI approach, but the delay between consecutive clock pulses is short and remains the same, independent of the number of stages. In the MSI approach, the total propagation delay is a function of the length of the Am25LS181 adder network. It is possible to have a combination of combinatorial carry

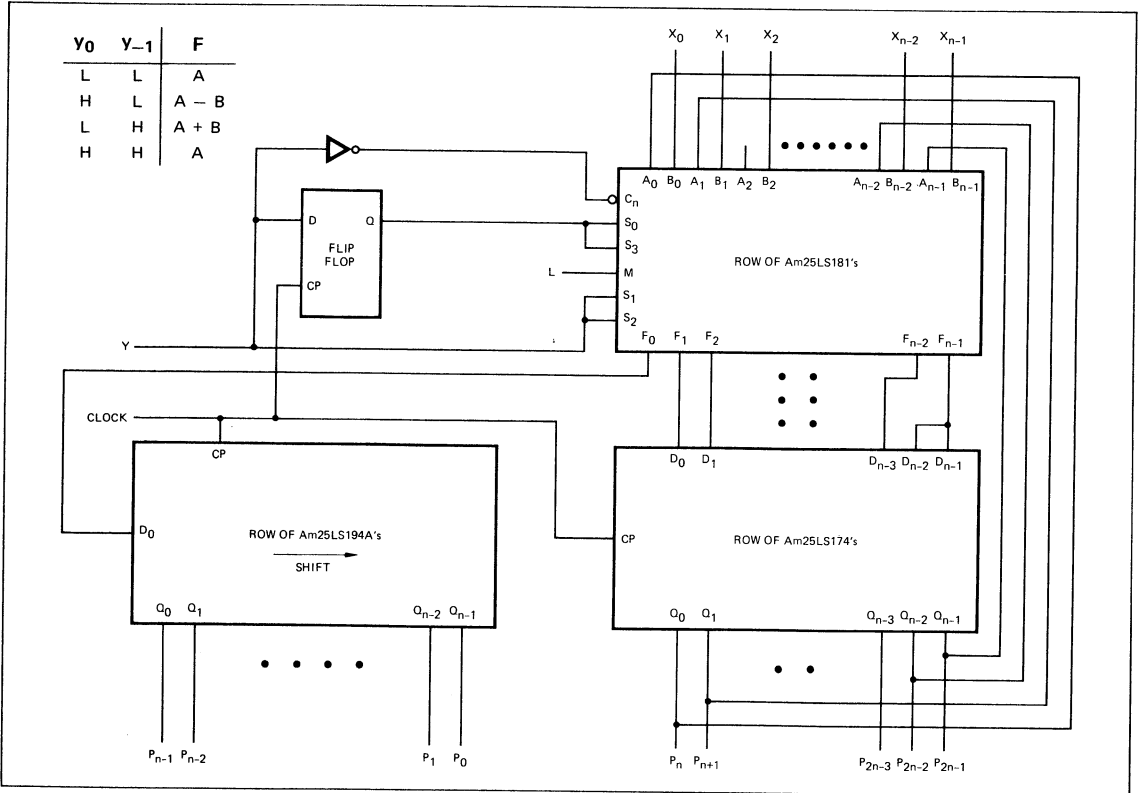


Figure 1. An MSI Implementation of the Serial/Parallel Multiplier Algorithm

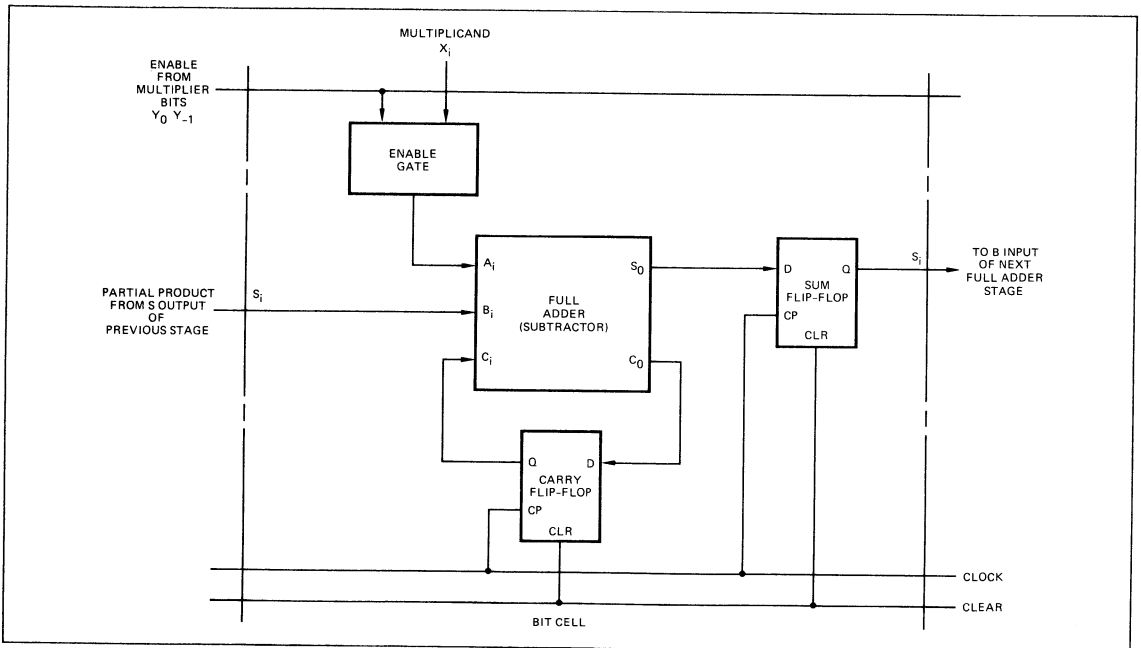


Figure 2. This Carry Save Cell Could Be Used in a Shift and Add Algorithm for a Serial/Parallel Multiplication

and stored carry by storing every second or fourth carry generated and so on. However, the best compromise between delay and complexity appears to be satisfied in low-power Schottky technology by incorporating an extra carry flip-flop at each multiplicand stage and storing the carry for each full adder.

UNDERSTANDING THE ITERATIVE CELL OF THE Am25LS14

In order to fully understand the iterative cell of the Am25LS14, it is necessary to view the cell block diagram of Figure 2. What is desired is to define the logic operation of the multiplicand enable gate and the full adder/subtractor. From the development of Booth's algorithm, it has been shown that y_0 and y_{-1} (y_a and y_{a-1} respectively) control the add/subtract function as well as the pass multiplicand/pass zero function. The full adder/subtractor and control gate, therefore, must have y_0 , y_{-1} and x_i as inputs. Also, the carry saved from the previous iteration is an input, C_i , as well as the sum bit, S_i , from the previous iteration. The adder/subtractor must generate a new sum bit, S_0 , and a new carry/borrow bit, C_0 .

For any multiplication, there is only one value of x_i at each cell. That is, x_i is either a logic 1 or a logic 0. Thus, each case for x_i can be treated separately. Let us assume that $x_i = 0$ as the input to cell shown in Figure 2. It is soon recognized that based on Booth's algorithm, the required operation is add nothing, subtract nothing or do nothing. Thus, if the carry flip-flop is reset initially, the only possible logic 1 into the cell is at the S_i input since $x_i = 0$ and $C_i = 0$ initially. This results because the value at both the B and C inputs to the adder/subtractor are always zero. Therefore, the carry flip-flop can never be set to a one because the carry out is always zero. Thus, S_0 is always set equal to the value at B and the cell executes a simple pass function. This is shown in the top 16 states of Table I. Table I shows all the combinatorial output states of the adder/subtractor as a function of the five input variables to the cell; these are x_i , y_0 , y_{-1} , S_i and C_i .

The more interesting case, obviously, is the condition where the x_i input is a logic 1 for the multiplicand bit at this cell. The easiest way to explain this case is to view the last 16 states of Table I. This should result in considerable misunderstanding not to mention the initial frustration.

Let's try to take this table apart and make some sense out of it. First of all, remember that due to the operation of Booth's algorithm, additions and subtractions must be interleaved. Two additions or two subtractions cannot be sequential. This is an extremely important key in understanding the cell operation.

In Table I, notice that states 16 through 19 execute a do nothing based on Booth's algorithm since $y_0 = 0$ and $y_{-1} = 0$. Likewise, states 20 through 23 execute an add the multiplicand to the running partial product since $y_0 = 0$ and $y_{-1} = 1$. States 24 through 27 requires the multiplicand to be subtracted from the running partial product and states 28 through 31 are also do nothing. It is essential to observe that only one time cycle can be spent in states 20 through 23 or 24 through 27. This is because two additions or subtractions cannot be sequential. Also, certain states result in definite possible state transitions depending on the new y_0y_1 value. For example, state 24 can only lead to states 21, 23, 29 or 31. State 23 can only go to states 16, 18, 24 or 26 on the next cycle and so forth. However, once in states 16 through 19, you can remain in states 16 through 19 indefinitely, and once in states 28 through 31 you can remain in states 28 through 31 indefinitely.

So what? After careful scrutinization, it will be realized that the sum, S_0 , and carry, C_0 , outputs of the adder/subtractor cell of Figure 2 can only represent the function of the block if the following is true:

- To define the operation of states 16 through 23, the S_0 output is weight 1 and C_0 is weight 2.
- To define the operation of states 24 through 31, the S_0 output is weight 1 and C_0 is weight -2.

This results in the carry/borrow definition for the adder/subtractor. Remembering that the running partial product is shifted before the next cycle, the c_i input of the full adder/subtractor is, of course, at weight +1 or -1 after the shift. Once Table I is accepted, all that remains is to generate the required logic for the cell. That is, the logic equations for S_0 and C_0 . Simply stated, the equations for the adder/subtractor cell are as follows:

$$S_0 = S_i \oplus C_i \oplus [X_i (y_{-1} \oplus y_0)]$$

$$C_0 = (S_i \oplus y_0) [C_i \oplus X_i (y_0 \oplus y_{-1})]$$

These are the equations implemented in each cell of the Am25LS14 with a slight modification to the MSB cell.

Table I
Function Table for an Am25LS14 Cell

State	X_i	y_0	y_{-1}	S_i	C_i	S_0	C_0
0	0	0	0	0	0	0	0
1	0	0	0	0	1	-	-
2	0	0	0	1	0	1	0
3	0	0	0	1	1	-	-
4	0	0	1	0	0	0	0
5	0	0	1	0	1	-	-
6	0	0	1	1	0	1	0
7	0	0	1	1	1	-	-
8	0	1	0	0	0	0	0
9	0	1	0	0	1	-	-
10	0	1	0	1	0	1	0
11	0	1	0	1	1	-	-
12	0	1	1	0	0	0	0
13	0	1	1	0	1	-	-
14	0	1	1	1	0	1	0
15	0	1	1	1	1	-	-
16	1	0	0	0	0	0	0
17	1	0	0	0	1	1	0
18	1	0	0	1	0	1	0
19	1	0	0	1	1	0	1
20	1	0	1	0	0	1	0
21	1	0	1	0	1	0	0
22	1	0	1	1	0	0	1
23	1	0	1	1	1	1	0
24	1	1	0	0	0	1	1
25	1	1	0	0	1	0	0
26	1	1	0	1	0	0	0
27	1	1	0	1	1	1	0
28	1	1	1	0	0	0	0
29	1	1	1	0	1	1	1
30	1	1	1	1	0	1	0
31	1	1	1	1	1	0	0



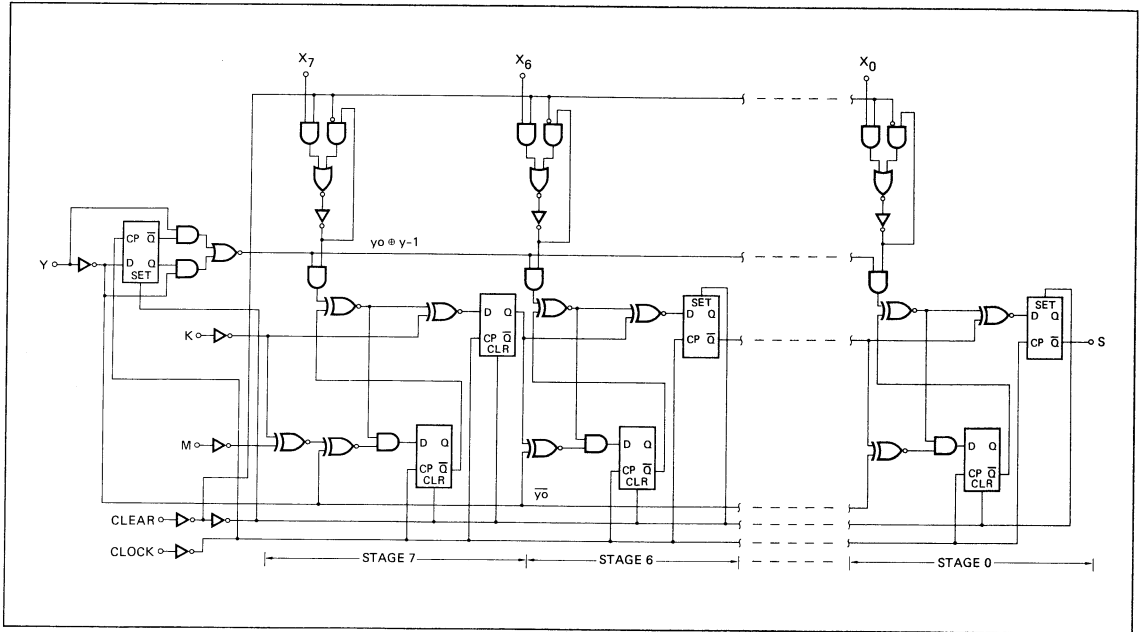


Figure 3.

LOGIC DIAGRAM

A full logic depiction of the Am25LS14 is shown in Figure 3. Each of the seven least significant cells of the device are identical. These are the cells shown as stage 0 through stage 6.

Only the eighth (MSB) cell (stage 7) has a modification to handle the Mode (M) and expansion (K) inputs to allow cascading. Also, the sum flip-flop output is connected to the opposite side compared to the other cells.

HOW TO MULTIPLY AND/OR DIVIDE IN TWO'S COMPLEMENT HARDWARE

By Roy Levy

A question that is asked of our application group almost daily is "How do I multiply and divide in two's complement hardware". AMD has designed a family of integrated circuits to aid systems' and subsystems' designers in solving some of the complicated arithmetic problems. These circuits are:

- Am25S05 — Schottky Four-Bit by Two-Bit Two's Complement Multiplier.*
- Am2505 — TTL Four-Bit by Two-Bit Two's Complement Multiplier.
- Am25L05 — Low-Power Four-Bit by Two-Bit Two's Complement Multiplier.
- Am2503 — Successive Approximation Register.
- Am25L03 — Low-Power Successive Approximation Register.
- Am25LS22 — Eight-Bit Serial/Parallel Register with Sign Extend.
- Am25LS14 — Eight-Bit Serial/Parallel Two's Complement Multiplier.
- Am25LS15 — Quad Serial Adder/Subtractor.

The problem of two's complement multiply can be solved using AMD devices in either of two ways dependent on speed requirements. One is by using the Am25LS14 and performing a serial by parallel multiply and iterating the algorithm through all "Y" bits of the serial multiplier word (see Figure 1). This particular solution assumes the use of an eight-bit data bus and loads an eight-bit multiplicand into Am25LS14 in two's complement notation and an eight-bit multiplier into the first Am25LS22. After 17 clock cycles, the 16-bit product will be forced into the two 8-bit Am25LS22 registers.

The second and faster method of two's complement multiplication is that of Figure 2. This method employs the use of the Am25S05. The connection symbology will be seen in Figure 3. This implementation can be modified for speed or

power by substituting the Am2505 or Am25L05 for the Am25S05; Table A shows a comparison of power and speed for these devices. Table B shows the trade-off when applied to a multiplier array. Rearranging the inputs allows for multiply in a modified number system; i.e., Sign-magnitude or two's complement by one's complement (see Figures 3 and 4).

Division can be accomplished by using the recursion algorithm (or trial and error). In this method (Figure 5), a trial quotient is formed and the product of the trial quotient and division is tested against the actual dividend and the result (sign) noted. If the sign is positive, the MSB quotient is set to a one; if not, a zero is stored. This procedure is repeated for all bits of the desired quotient—MSB first, LSB last. The output of this divide is available in serial or in parallel form. Specifically, the divisor, dividend and trial quotient are all treated as two's complement numbers. Note that the first trial value is integer -1 . The operations performed are:

For Q_S , the sign digit of the quotient:

If $D_7 = 0$ and $-\frac{D}{2} < P$, Set $Q_S = 0$ Otherwise $Q_S = 1$

If $D_7 = 1$ and $-\frac{D}{2} < P$, Set $Q_S = 1$ Otherwise $Q_S = 0$

For the remaining quotient digits:

If $D_7 = 0$ and $T_{i-1}D + \frac{D}{2} < P$, Set $Q_i = 1$ otherwise $Q_i = 0$

If $D_7 = 1$ and $T_{i-1}D + \frac{D}{2} < P$, Set $Q_i = 0$ otherwise $Q_i = 1$

where T_i is the i th trial value held in the SAR.

*Further applications of the Am25S05 are shown in "The Am25S05, Am2505 and Am25L05 2's Complement Digital Multipliers" application note contained in the Advanced Micro Devices' Schottky and Low-Power Data Book.

APPLICATIONS

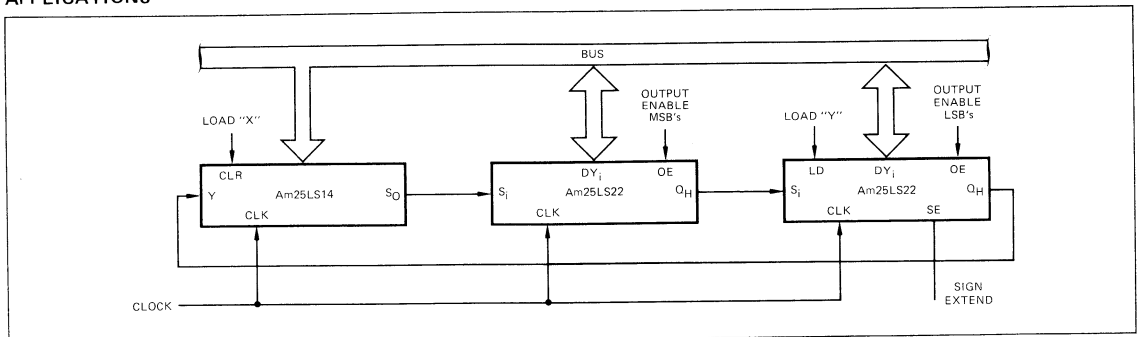


Figure 1. Bus Oriented 8-Bit x 8-Bit Multiplier with 16-Bit Product.

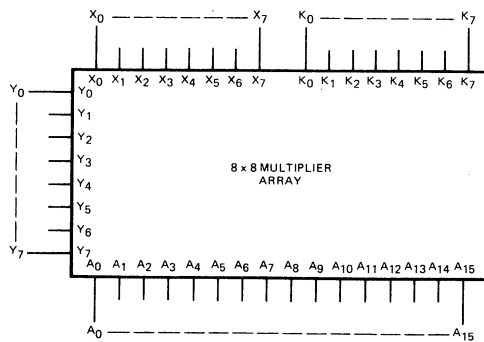
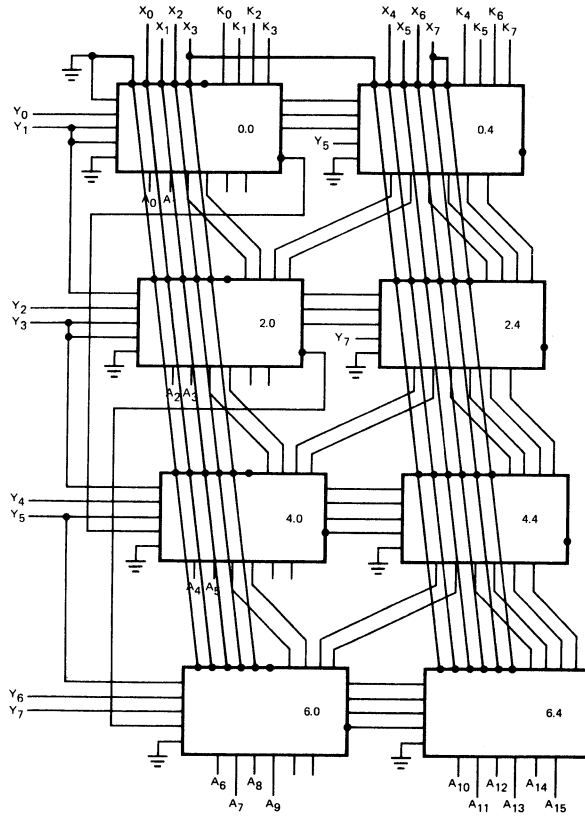


Figure 2. 8 x 8 Multiplication Array for 2's Complement Numbers. Both the Actual Connection Diagram and System Block Diagram are Shown.

Figure 3.

CONNECTION DIAGRAMS

Within this Appendix, the symbol shown at left below is used to represent the Am25S05, Am2505, or Am25L05. The symbol at left should be interpreted as equivalent to the symbol at right.

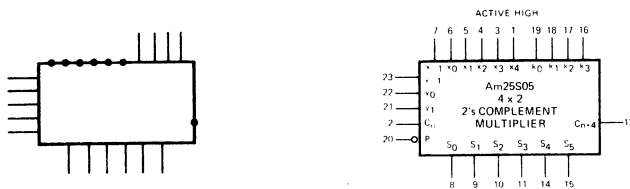


Table A-1 is a summary of the typical switching characteristics for each path through the multiplier.

TABLE A
TYPICAL SWITCHING CHARACTERISTICS

$$\left(\frac{t_{PHL} + t_{PLH}}{2} \right)$$

PATH	Am25S05	Am2505	Am25L05	UNIT
C _n to C _{n+4}	8.5	13.5	32.5	ns
C _n to S ₀₃	11.0	16.5	36.0	ns
C _n to S ₄₅	14.0	19.5	44.0	ns
k to C _{n+4}	8.25	13.5	31.0	ns
k to S ₀₃	11.5	16.5	36.5	ns
k to S ₄₅	14.0	21.5	51.5	ns
X to C _{n+4}	17.5	21.0	63.5	ns
X to S ₀₃	21.0	25.0	70.0	ns
X to S ₄₅	22.5	29.5	85.0	ns
Y to C _{n+4}	21.5	33.0	75.0	ns
Y to S ₀₃	23.0	35.0	83.5	ns
Y to S ₄₅	25.0	38.5	93.5	ns
I _{CC} (TYP.)	120	90	30	mA

TABLE B
TYPICAL SPEED & POWER
FOR
TWO'S COMPLEMENT MULTIPLICATION

ARRAY SIZE		Am25S05		Am2505		Am25L05	
Y • X	# DEVICES	SPEED ns	POWER WATTS	SPEED ns	POWER WATTS	SPEED ns	POWER WATTS
4x4	2	39	1.2	60	0.9	145	0.3
4x8	4	55	2.4	83	1.8	186	0.6
4x12	8	64	4.8	96	3.6	219	1.2
8x8	8	76	4.8	115	3.6	262	1.2
8x12	12	94	7.2	143	5.4	320	1.8
8x16	16	102	9.6	156	7.2	353	2.4
12x12	18	115	10.8	175	8.1	396	2.7
12x16	24	132	14.4	203	10.8	454	3.6
12x20	30	141	18.0	216	13.5	487	4.5
16x16	32	153	19.2	235	14.4	530	4.8
16x20	40	171	24.0	263	18.0	588	6.0
16x24	48	179	28.0	276	21.6	621	7.2
20x20	50	192	30.0	295	22.5	664	7.5
20x24	60	209	36.0	323	27.0	722	9.0
20x28	70	218	42.0	336	31.5	755	10.5
24x24	72	230	43.2	355	32.4	798	10.8
24x28	84	248	48.0	383	36.0	856	12.0
24x32	96	256	52.8	396	39.6	889	13.2
28x28	98	269	54.0	415	40.5	932	13.5
28x32	112	286	62.4	443	46.8	990	15.6
32x32	128	307	72.0	475	54.0	1066	18.0

NOTE: With Curry's Interchanged to Reverse Speed.

algorithm between the sign bit and the rest of the bits is automatically taken care of.

The D/2 factor in the equations is used to round off the quotient. A double length dividend is assumed. The Am9324 comparator array is wired for a two's complement comparison with the sign digit of the product and dividend crossed over, the dividend sign bit forming part of the multiplier word and the product sign bit forming part of the dividend word.

It is evident that the divider can be used as either a divider or a multiplier (Figure 6) by substituting the inputs, outputs and providing buffering. The required control function is subject to the specific usage. Figure 7 indicated the application with bus-oriented computers such as Am9080A, 8080A, 6800, etc. To achieve this configuration, it will be necessary to add storage registers and three-state drivers. As most machines are clocked, the Divisor/Multiplier and dividend registers must be

provided to retain this data for the period of operation. In order to avoid interference with the bus structure, all replies must be isolated from the data bus until requested by the machine (CPU). Certain exceptions can be made if the system will tolerate a temporary clock, stoppage while the multiplier/divider is operating. Although the operation is fast, timing consideration must be factored. The slowest operation (divide) will produce results in 16 clock pulses after completion of the loading and stabling operations. The typical sequence is as follows:

Multiply Sequence

1. Load status
2. Load multiplicand
3. Load multiplier
4. Sequence ≈ four clocks
5. Read LSB product
6. Read MSB product

Divide Sequence

1. Load status
2. Load LSB dividend
3. Load MSB dividend
4. Load divisor
5. Sequence ≈ 12 clocks
6. Read quotient

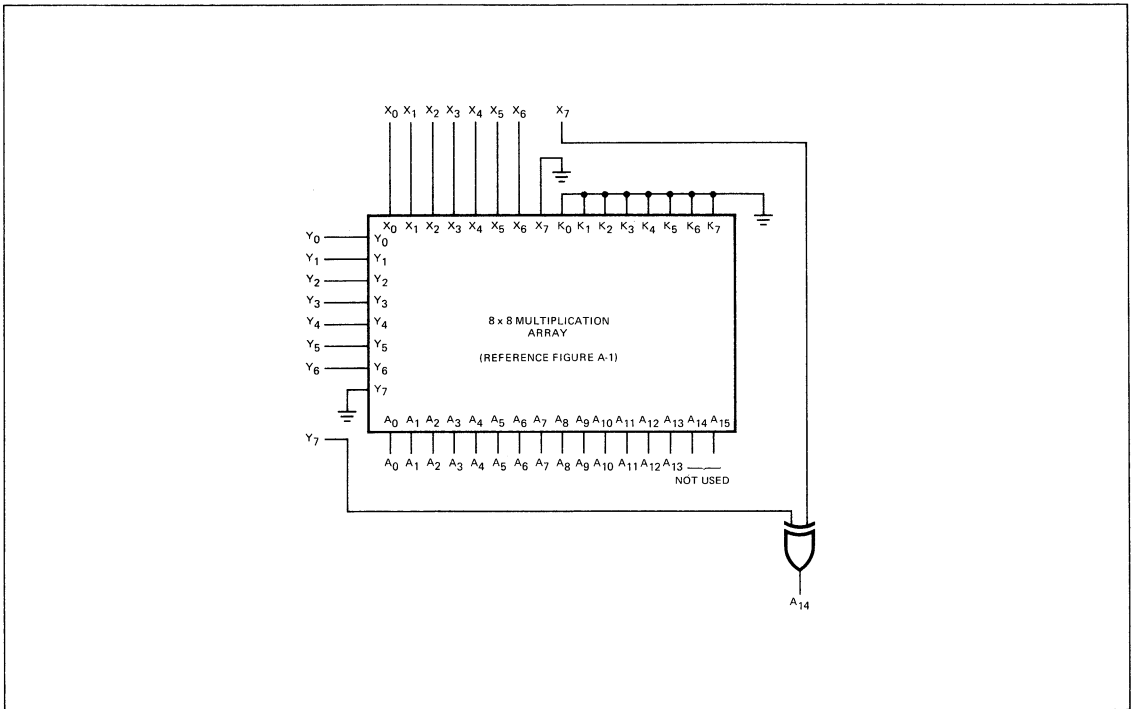


Figure 3. 8 x 8 Multiplication Array for Sign-magnitude Numbers.

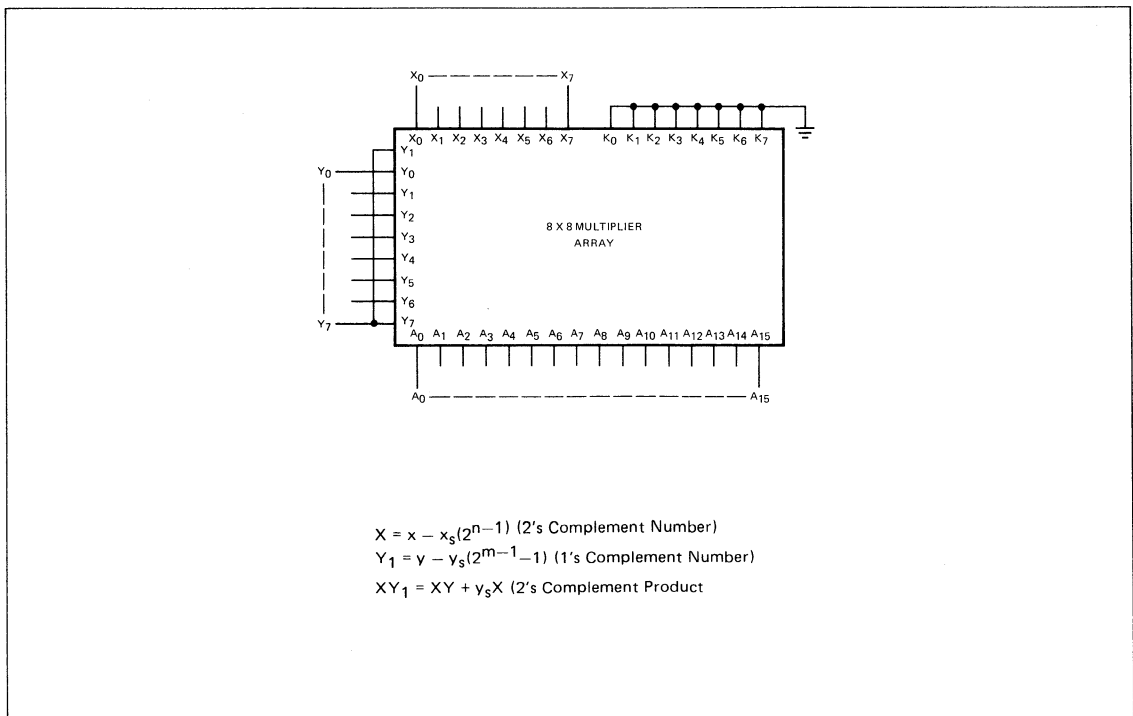


Figure 4. 2's Complement Multiplicand, 1's Complement Multiplier and 2's Complement Product.

How to Multiply And/Or Divide

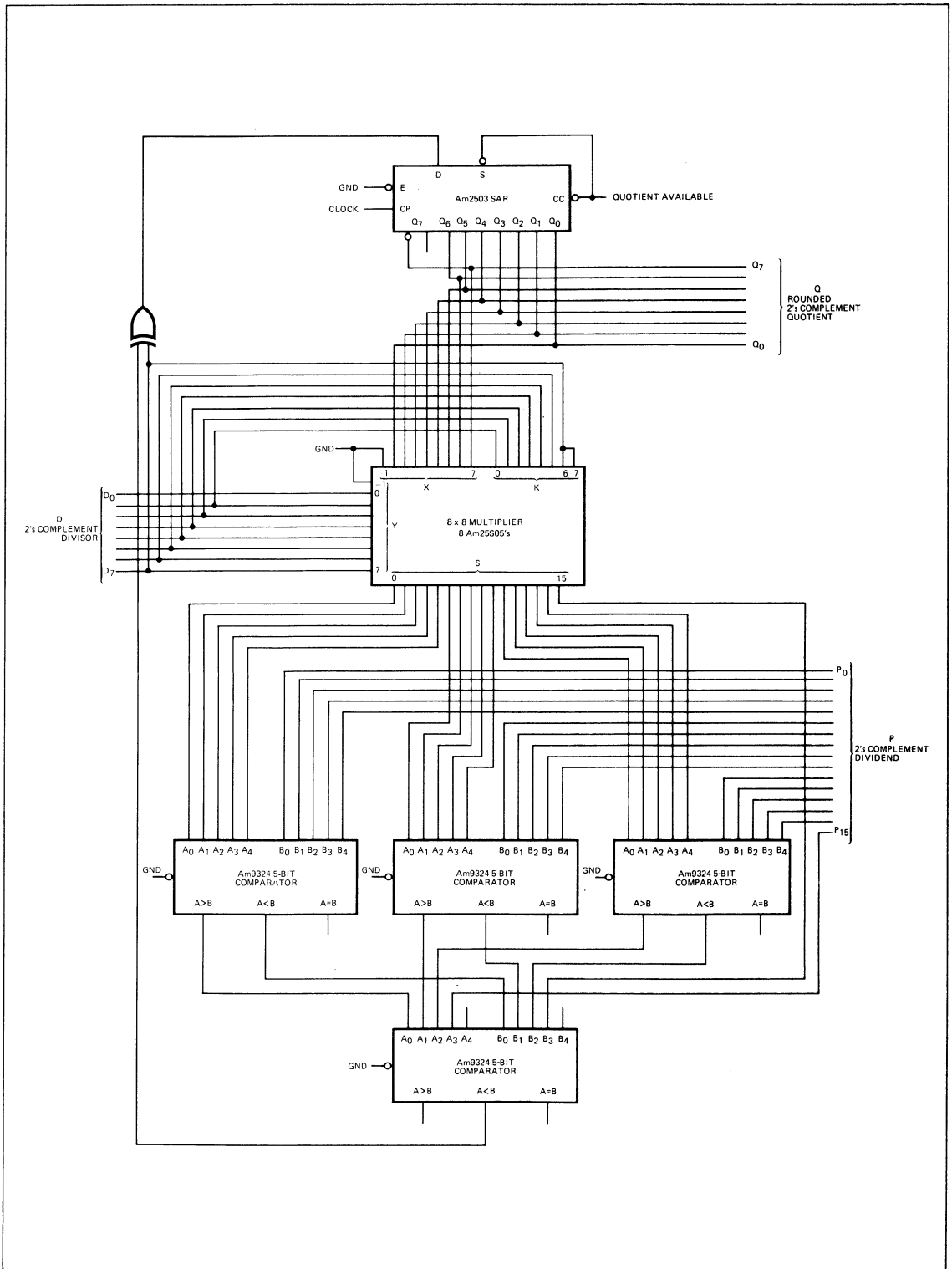


Figure 5. 2's Complement Rounded Division.

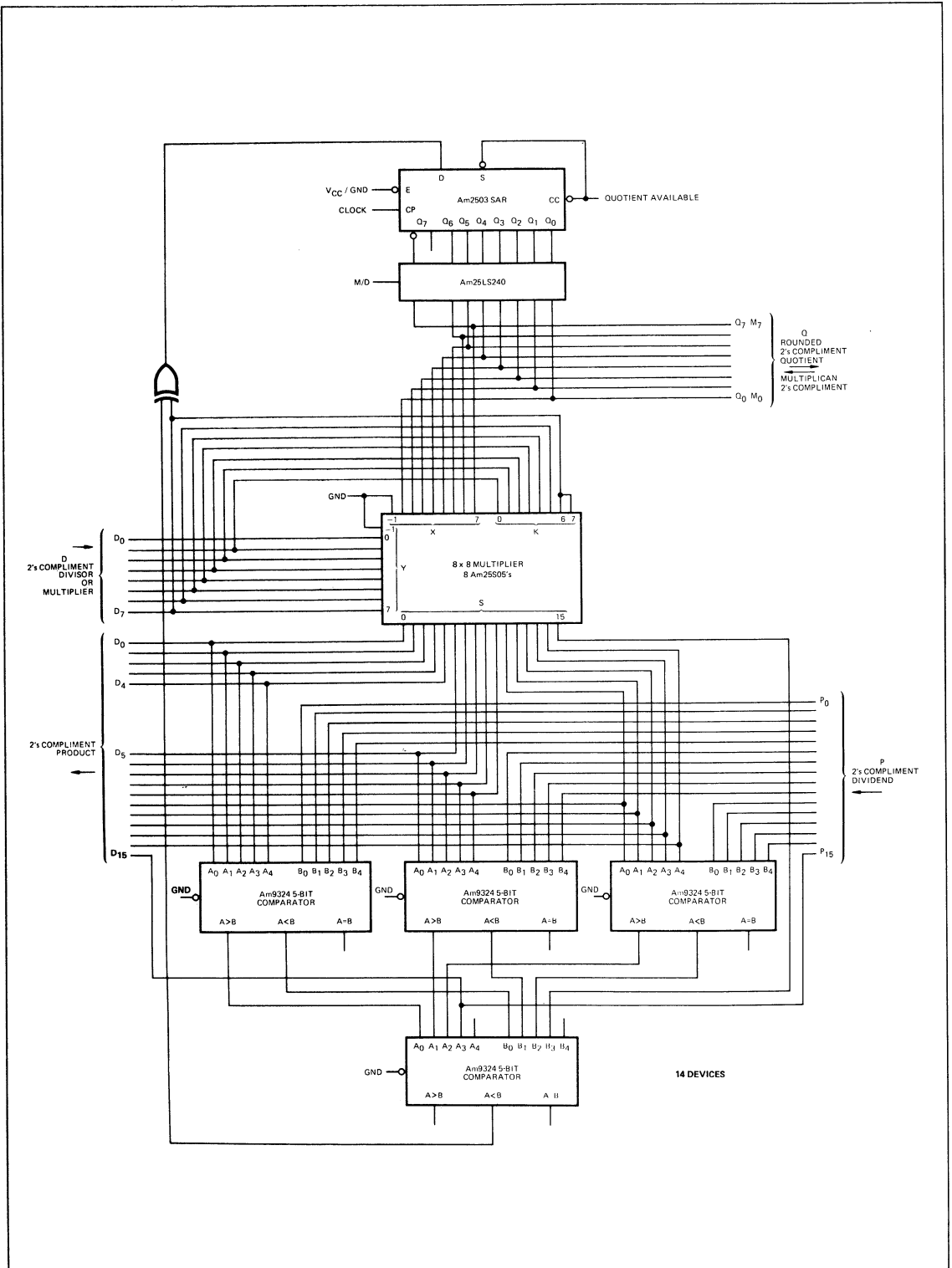
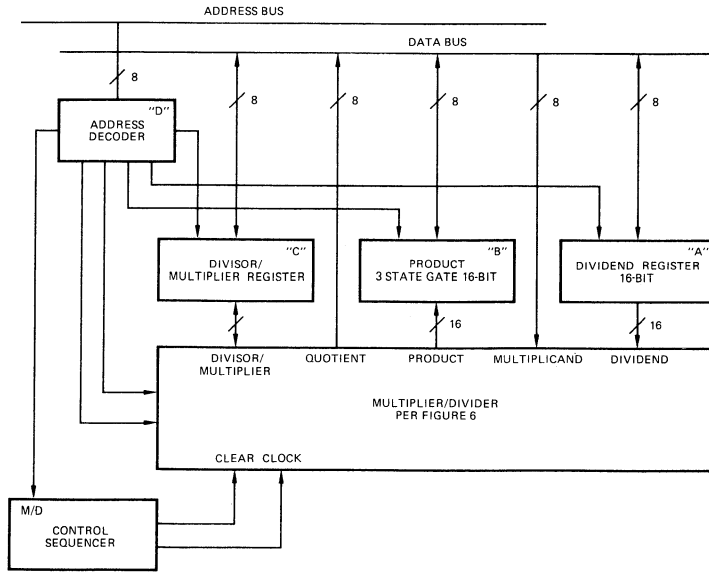


Figure 6. 2's Complement Multiplier/Divider.



SUGGESTED PARTS

- A - 2 ea. Am25LS374
- B - 2 ea. Am25LS240
- C - 1 ea. Am25LS374
- D - 1 ea. Am25LS138

Figure 7. 8-bit by 8-bit Multiplier/Divider.

The Am25S05, Am2505 and Am25L05 Schottky, Standard and Low Power TTL 2's Complement Digital Multipliers

By John R. Mick

INTRODUCTION

This application note is an updated and expanded version of the "A 2's complement Digital Multiplier — the Am2505" application note by R.C. Ghest, published in November, 1971. The device is now available in three technologies. The Am25S05 is a very high speed 2's complement multiplier built using advanced Schottky technology. The Am2505 is a standard power MSI element for medium speed applications. The Am25L05 is a low-power MSI circuit for slower speed applications.

The Am25S05, Am2505, and Am25L05 can be used in iterative arrays to perform multiplication of 2's complement numbers with a minimum of hardware. The new Am25S05 provides the capability to perform very high speed direct hardware multiplications and is especially suited for real-time digital processing applications. These devices will find applications in minicomputers, recursive or non-recursive digital filters, Fast Fourier Transform processors, adaptive digital integrators and many other digital implementations of special arithmetic algorithms.

At the present time, digital machines perform multiplication using either serial techniques, serial-parallel techniques, or all-parallel techniques. The multiplication speeds can be very slow to very fast depending on the exact hardware implementation used and the hardware constraints imposed. The Am25S05, Am2505, and Am25L05 are particularly suited for either all parallel multiplication or serial-parallel multiplication.

MULTIPLICATION DEFINITION

According to Webster's Dictionary, multiplication is "a mathematical operation that at its simplest is an abbreviated process of adding an integer to itself a specified number of times and that is extended to other numbers in accordance with laws

that are valid for integers." This definition is particularly appropriate for binary numbers in that all hardware binary multiplication schemes make an "add" or "no-add" decision and maintain the "weighting" rules of binary numbers. The two numbers involved in the operation are usually called the multiplicand (the number to be multiplied) and the multiplier (the number that multiplies) with the result being called the product (later in this application note the partial products or partial sums will be important).

Binary multiplication is performed as in the following four digit example. The terms X and Y are:

$$X = x_0(2^0) + x_1(2^1) + x_2(2^2) + x_3(2^3)$$

$$X = x_0(1) + x_1(2) + x_2(4) + x_3(8)$$

$$Y = y_0(1) + y_1(2) + y_2(4) + y_3(8)$$

where x_i and y_i can assume a "0" or "1" value for $i = 0, 1, 2$ or 3 .

If X is the multiplicand and Y is the multiplier, the product S of X·Y is

$$\begin{aligned} S = X \cdot Y = & y_0(1) [x_0(1) + x_1(2) + x_2(4) + x_3(8)] \\ & + y_1(2) [x_0(1) + x_1(2) + x_2(4) + x_3(8)] \\ & + y_2(4) [x_0(1) + x_1(2) + x_2(4) + x_3(8)] \\ & + y_3(8) [x_0(1) + x_1(2) + x_2(4) + x_3(8)] \end{aligned}$$

In the above example, it can be seen that three additions are required to generate the product S of X·Y; the first two of these are usually called partial products or partial sums. In order to examine the weighting of the binary numbers in the above example, the complete partial product solution is shown in Figure 1 and the weights of the x terms and y terms have been combined.

			Multiplicand	$x_3(8)$	+	$x_2(4)$	+	$x_1(2)$	+	$x_0(1)$							
			Multiplier	$y_3(8)$	+	$y_2(4)$	+	$y_1(2)$	+	$y_0(1)$							
				$x_3y_0(8)$	+	$x_2y_0(4)$	+	$x_1y_0(2)$	+	$x_0y_0(1)$							
			$x_3y_1(16)$	+	$x_2y_1(8)$	+	$x_1y_1(4)$	+	$x_0y_1(2)$								
			Carry (32)	+	$Ps_4(16)$	+	$Ps_3(8)$	+	$Ps_2(4)$	+	$Ps_1(2)$	+	$Ps_0(1)$				
			$x_3y_2(32)$	+	$x_2y_2(16)$	+	$x_1y_2(8)$	+	$x_0y_2(4)$								
			Carry (64)	+	$Ps_5(32)$	+	$Ps_4(16)$	+	$Ps_3(8)$	+	$Ps_2(4)$	+	$Ps_1(2)$	+	$Ps_0(1)$		
			$x_3y_3(64)$	+	$x_2y_3(32)$	+	$x_1y_3(16)$	+	$x_0y_3(8)$								
			$s_7(128)$	+	$s_6(64)$	+	$s_5(32)$	+	$s_4(16)$	+	$s_3(8)$	+	$s_2(4)$	+	$s_1(2)$	+	$s_0(1)$

Figure 1. Multiplication of Two Unsigned 4-bit Numbers X and Y

The $s_7(128)$ term represents the carry out of the final summation. As is seen, the multiplication of two 4-bit unsigned words results in an 8-bit product. This can be extended to a general statement; that is, the multiplication of a m -bit unsigned number with a n -bit unsigned number gives a $m + n$ bit resultant unsigned product. This number may be truncated of course and rules will be given later for determining the resulting accuracy when the hardware is being reduced.

It should be recognized that the product terms associated with y_0 and y_1 can be added in one adder and the product terms associated with y_2 and y_3 can be added in a second adder at the same time; thereby giving two partial products after one adder propagation delay time. These two partial sums can then be added in a third adder to give the resultant product of the multiplication.

One technique for reducing multiplication time that is presently being used in serial and serial-parallel multipliers is to ignore addition when the multiplier bit is a logic "0." When this is done the number of terms to be added is equal to the number of 1's in the multiplier word. This method can be extended in such a way that strings of 1's can also be ignored—this leads to an important new technique for performing high speed multiplication. This technique will be discussed in greater detail later.

Two's Complement				Decimal Number
Sign bit	2^2	2^1	2^0	
-2^3				
-8	4	2	1	
0	1	1	1	+7
0	1	1	0	+6
0	1	0	1	+5
0	1	0	0	+4
0	0	1	1	+3
0	0	1	0	+2
0	0	0	1	+1
0	0	0	0	0
1	1	1	1	-1
1	1	1	0	-2
1	1	0	1	-3
1	1	0	0	-4
1	0	1	1	-5
1	0	1	0	-6
1	0	0	1	-7
1	0	0	0	-8

Figure 2. Full Definition of a 4-bit Two's Complement Binary Number

TWO'S COMPLEMENT NOTATION

This section is presented as a quick review of the two's complement numbering system and is intended to give insight for the designer not familiar with two's complement notation. The two's complement numbering system is a technique for describing positive and negative numbers in a convenient notation. When contrasted with other numbering systems such as sign-magnitude and one's complement, it has the advantage of only having one representation for the number "zero." Also, two's complement numbers can be added or subtracted without concern for the sign of each number as the result will be correct in two's complement notation.

In 2's complement notation, the sign bit is a logical "0" for positive numbers and a logical "1" for negative numbers. Four bits may be used to represent the numbers +7 to -8 as shown in Figure 2. Notice that the sign bit does carry magnitude information that has a negative value.

From this example, it is readily apparent that the magnitude of the negative numbers is not represented by its associated magnitude bits if the sign bit is ignored as is the case for the positive numbers. One way to find the absolute magnitude of a negative 2's complement number is to invert all bits and add plus binary one as in the example below:

```

1011  Negative 2's complement number
0100  Inverted
+ 0001 One Added
-----
0101  Result
    
```

From this example, it is seen that the magnitude of this negative numbers is five.

Likewise, to form a negative 2's complement number, the positive representation is taken, inverted, and plus binary one is added as shown.

```

Positive number +3
Binary representation      0011
Inverted                   1100
One added                   + 0001
-----
Minus three in two's complement 1101
    
```

The advantage of two's complement in many computers and digital processors is that addition and subtraction can be performed without regard to whether the numbers being added or subtracted are positive or negative. Examples of addition are shown in Figure 3. Note that overflows are discarded.

0001	+1	0001	+1	1110	-2
0101	+5	1111	-1	0110	+6
0110	+6	(1)0000	0	(1)0100	+4
0110	+6	1010	-6	1110	-2
1110	-2	0011	+3	1101	-3
(1)0100	+4	1101	-3	(1)1011	-5

Figure 3. Examples of Two's Complement Addition

Subtraction is much like addition except that the number being subtracted (subtrahend) must be inverted and have one added to its value. It is then added to the minuend. This addition of +1 represents no problem in the hardware because the carry in (c_n) of the least significant adder can be used for this purpose — not an additional adder. Figure 4 shows examples of subtraction.

Minuend	0001 +1	1110 -2	1110 -2	1010 -6
Subtrahend	0101 +5	0110 +6	1101 -3	1101 -3
Minuend	0001	1110	1110	1010
Inverted Subtrahend	<u>1010</u>	<u>1001</u>	<u>0010</u>	<u>0010</u>
Add	1011	0111	0000	1100
Add One	<u>0001</u>	<u>0001</u>	<u>0001</u>	<u>0001</u>
Result (Binary)	1100	1000	0001	1101
Result (Decimal)	-4	-8	+1	-3

Figure 4. Examples of Two's Complement Subtraction.

From these examples, one might conclude that multiplication is simply the product of one 2's complement number with the other. Unfortunately, this is not correct for negative numbers. One obvious technique for multiplication in which negative numbers are represented by 2's complements is to determine the signs and magnitudes of the operands, multiply the magnitudes, and then if the result is negative, cast the result into 2's complement form. It seems preferable, however, to devise a scheme for multiplying such numbers more simply. Booth's method will be considered for this purpose.

BOOTH'S ALGORITHM

In the usual methods of digital multiplication, the multiplier digits are examined in turn and when the multiplier digit is a logical "1," the multiplicand is added to the running partial sum in the appropriate weight. For each multiplier digit, there is a relative one-digit shift between the multiplicand and partial sum whether there has been an addition or not. Booth's algorithm provides a tool whereby more than one shift at a time may be made, depending on the grouping of strings of logic 1's or logic 0's. This multiple shifting ability may be used to "speed up" the multiplication process.

The basic algorithm as developed by Booth is as follows: y_i is the i -th most significant bit of an n -bit multiplier representation. y_{-1} is zero. y_0 is the least significant bit. y_{n-1} is the sign bit. X is the multiplicand.

Starting with $i = 0$, y_i and y_{i-1} are compared:

- 1.) If $y_i = y_{i-1}$; add $0X$.
- 2.) If $y_i = 1$ and $y_{i-1} = 0$; subtract $1X$ (the multiplicand) from the partial product. (Add the 2's complement).
- 3.) If $y_i = 0$ and $y_{i-1} = 1$; add $1X$ to the partial product.

Two examples of these rules are shown in Figure 5.

Example 1:

1 0 1 1 1	= -9			
0 1 0 1 1 (0)	= +11			
0 0 0 0 0 1 0 0 1	$y_0 = 1$	$y_{-1} = 0$		
0 0 0 0 0 0 0 0	$y_1 = 1$	$y_0 = 1$		
1 1 1 0 1 1 1	$y_2 = 0$	$y_1 = 1$		
0 0 1 0 0 1	$y_3 = 1$	$y_2 = 0$		
1 0 1 1 1	$y_4 = 0$	$y_3 = 1$		
(1) 1 1 0 0 1 1 1 0 1	= -99			

Example 2:

1 1 0 1 1	= -5			
1 1 0 0 1 (0)	= -7			
0 0 0 0 0 0 1 0 1	$y_0 = 1$	$y_{-1} = 0$		
1 1 1 1 1 0 1 1	$y_1 = 0$	$y_0 = 1$		
0 0 0 0 0 0 0	$y_2 = 0$	$y_1 = 0$		
0 0 0 1 0 1	$y_3 = 1$	$y_2 = 0$		
0 0 0 0 0	$y_4 = 1$	$y_3 = 1$		
(1) 0 0 0 1 0 0 0 1 1	= +35			

Figure 5. Examples of Booth's algorithm for two's complement multiplication

Based on these rules as developed by Booth, it is a straight forward process to make a table of desired action for each of the four possible two-bit combinations under inspection. This is shown below. K is the partial product before this level of the algorithm and is zero initially.

Table of Operation for Booth's Algorithm			
y_{i-1}	y_i	Function	Partial Product
0	0	Do nothing	$K + 0$
1	0	Add X	$K + X$
0	1	Subtract X	$K - X$
1	1	Do nothing	$K + 0 = K - 0$

As stated earlier, one of the initial goals is to develop an algorithm that provides the ability to look ahead more than one bit at a time. Therefore, the above table for one multiplier bit y_i is expanded to Table I for two multiplier bits, y_i and y_{i+1} .

TABLE I — BOOTH'S ALGORITHM FOR TWO MULTIPLIER BITS TAKEN SIMULTANEOUSLY.

Input			For	For	Net Result
Y_{i-1}	Y_i	Y_{i+1}	Y_{i-1}, Y_i	Y_i, Y_{i+1}	Y_{i-1}, Y_i, Y_{i+1}
0	0	0	K+0	K+0	K+0
1	0	0	K+X	K+0	K+X
0	1	0	K-X	K+2X	K+X
1	1	0	K-0	K+2X	K+2X
0	0	1	K+0	K-2X	K-2X
1	0	1	K+X	K-2X	K-X
0	1	1	K-X	K-0	K-X
1	1	1	K-0	K-0	K-0

From Table I for two multiplier bits, the following conclusions can be drawn:

- 1.) The y_{i+1} bit can be used as an add/subtract control where logic "0" is add and logic "1" is subtract.
- 2.) The function $y_{i-1} \oplus y_i$ can be used as a X weight control indicating the addition or subtraction of X to the partial product K.
- 3.) The function $y_{i-1} y_i \bar{y}_{i+1} + \bar{y}_{i-1} \bar{y}_i y_{i+1}$ can be used as a 2X weight control indicating the addition or subtraction of 2X to the partial product K.
- 4.) When in the subtract mode, the 2's complement of X (\bar{X} plus one) is added. Thus the x_i bits are exclusive OR'ed with the add/subtract control y_{i+1} . The plus one is generated in the partial product LSB by connecting the y_{i+1} to the first c_n of the adder used to add X and K.
- 5.) When 2X is being subtracted, the carry into the second LSB of the partial product is generated by connecting the first c_n to y_{i+1} and x_{-1} to logic 0.

Thus, all required functions of Table I can be implemented using combinatorial logic elements. The resultant output is a "partial product" of the total multiplication product. Remember that if y_{i+1} is 1, then y has been treated as a negative number up to that point so the partial product may not really be correct yet.

Both $y_{i-1} \oplus y_i$ and $y_{i-1} y_i \bar{y}_{i+1} + \bar{y}_{i-1} \bar{y}_i y_{i+1}$ are symmetric functions. This provides the ability to change from positive logic to negative logic ($X = \bar{X}, Y = \bar{Y}$) with the combinatorial functions remaining unchanged.

THE AM25S05

The Am25S05 is an advanced Schottky MSI circuit that implements the algorithm previously developed in this application note. It can be used to multiply signed or unsigned numbers in various number representations and performs multiplications in either positive or negative logic. This discussion applies to the Am2505 and Am25L05 as well; but the Am25S05 has been assumed to provide a single device for discussion purposes.

The logic diagram of the Am25S05 is shown in Figure 6. The logic symbols and connection diagram are shown in Figure 7. The Am25S05 consists of five parts: a multiplier decoder, a shifting array, a complementer, a high speed adder, and an overflow and sign control.

1.) Multiplier Decoder

The multiplier decoder generates the required control signals for the shifting array and complementer. First, it decodes whether 0X, 1X or 2X of the X multiplicand is to be added to the incoming partial product. Second, the multiplier decoder generates the add/subtract command. The decoder generates the functions.

$$A = y_{i-1} \oplus y_i \quad \text{1X used}$$

$$B = y_{i-1} y_i \bar{y}_{i+1} + \bar{y}_{i-1} \bar{y}_i y_{i+1} \quad \text{2X used}$$

$$C = \bar{P} \bar{y}_{i+1} + P(y_{i+1}A + \bar{y}_{i-1} y_i) \quad \text{add/subtract}$$

(P input LOW = positive logic; P input HIGH = negative logic; P defined true for negative logic).

The "zero" times the multiplicand is obtained by $\bar{A}\bar{B}$. The P input controls the add/subtract sequence so that the multiplier can work in either the positive or negative logic representation. The function includes terms to handle logic "0 X" independent of the positive or negative logic representation when the decoding functions A and B are both false.

2.) Shifting Array

The shifting array generates 0, 1 or 2 times the multiplicand and applies this to the complementer. X is inverted through the shifting array and "0" is implemented as all HIGH's out of the array. The x_{-1} input is used to shift up the next lower order bit for the 2X function.

3.) Complementer

The complementer consists of a set of exclusive-NOR circuits controlled by the add/subtract function. The add command applies a "0" to each exclusive-NOR while a subtract applies a "1" to each exclusive-NOR. The add command thereby causes each output of the shifting array to be inverted. Thus, the x_i inputs are applied non-inverted to the high speed adder in the add mode and applied inverted in the subtract mode.

4.) High-Speed Adder

The high-speed adder is a 4-bit high-speed parallel carry look-ahead adder that adds the selected function of the multiplicand, X, to the partial product presented at the K inputs. The adder also has a carry input, C_n ; a carry output C_{n+4} ; and four sum outputs, S_0 to S_3 .

5.) Overflow and Sign Control

At the most significant end of the array, i.e. where the sign bits are processed, a problem arises when an overflow occurs as a result of (a) an addition or subtraction or (b) the need to use 2X in the adder. To overcome these overflow situations, the sign digits of the multiplicand and partial product must be repeated twice. Luckily some logic minimization is possible and the S_4 and S_5 outputs, which are the most significant bits of the 6-bit signed product, can be generated quite easily. These two outputs are required only at the most significant end of each iterative step of a multiplication. In order to re-

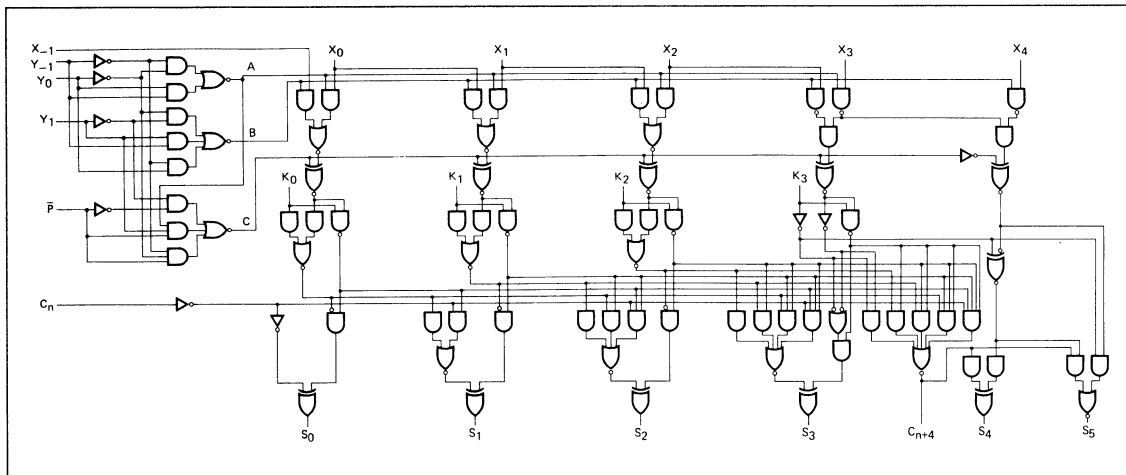


Figure 6. Logic Diagram for the Am25S05

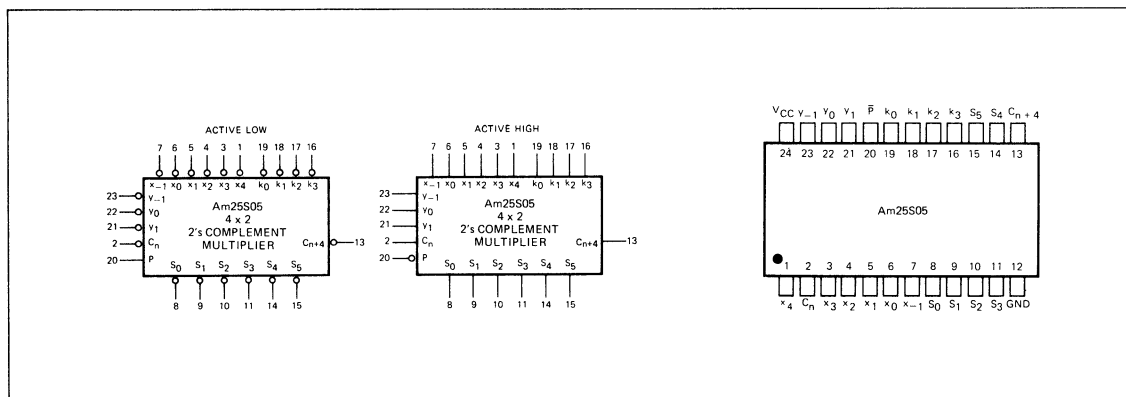


Figure 7. Logic Symbol and Connection Diagram for the Am25S05

duce input loading on x_3 , an additional x_4 input is provided which is a part of this overflow circuitry. The x_4 input must be connected to x_3 at the most significant end of the array only and can be left unconnected elsewhere.

ITERATIVE ARRAYS USING THE Am25S05

Since the Am25S05 is a 2 x 4 multiplier and performs the arithmetic function $S = XY + K$, it can be used as an iterative cell in multiplication schemes. The number of multiplier devices required for the multiplication of a n-bit X by an m-bit Y is given by

$$\text{Number of devices} = \left(\frac{n}{4}\right) \left(\frac{m}{2}\right)$$

where X and Y are the multiplicand and multiplier, respectively. (Note - fractions must be rounded up).

When the array is extended, only the S_0 through S_3 outputs are used in the partial product until the most significant end of the array is reached. Then, the S_4 and S_5 outputs are used for the most significant bits. Thus, a 4 x 2 multiplication

gives a 6-bit output; an 8 x 2 multiplication gives a 10-bit output; a 12 x 2 multiplication gives a 14-bit output and so forth. For the 12 x 2 multiplication case, S_0 through S_3 are the outputs of the two least significant multipliers and S_0 through S_5 are the outputs of the most significant multiplier to provide the 14-bit result. When the multiplier array is expanded in the Y direction, it is expanded on a row by row basis. The S outputs of one row are connected to the K inputs of the following row that are shifted up by two bits in the X direction (A weight of $2^2 = 4$). The two least significant output bits not connected (S_0 and S_1) provide two of the array outputs.

Figure 8 shows four Am25S05's connected to form a 4 x 8 array that produces a 2's complement product from a 4-bit 2's complement multiplier and an 8-bit 2's complement multiplicand. The scheme is shown for the positive logic representation; for the negative logic representation, P must be held high rather than LOW, and '1's and '0's must be reinterpreted. Since the first iteration is treated as if the previous operation were an addition, the x_{-1} and y_{-1} inputs are held at logic '0'. The S_4 and S_5 outputs are ignored except at the most significant edge of the array. The K inputs allow the accumulation

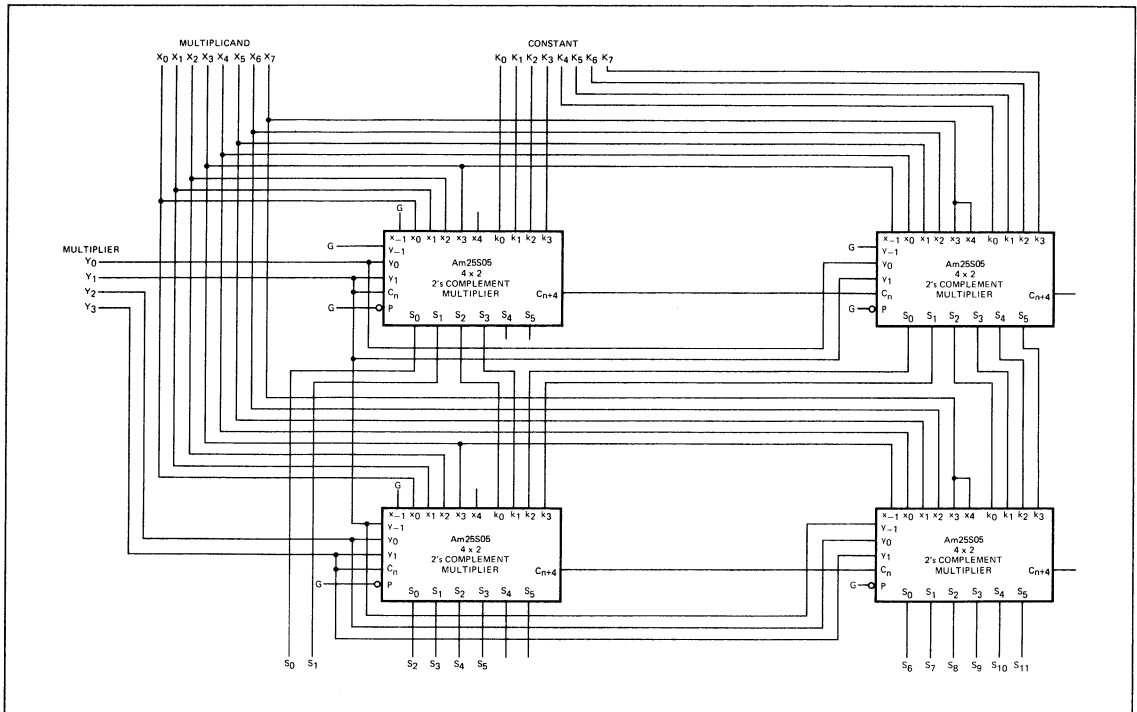


Figure 8. 2's Complement 8 x 4 Multiplication. Active High Levels

of partial products as information passes through the array.

Since at the first stage the partial product does not exist, the K inputs can be used to add in a number at the least significant end of the product. Otherwise the K inputs should be held at logic '0'. This feature is very useful as many arithmetic processes consist of a series of multiplication and additions, and these K inputs may save additional devices. For multiplication with longer word lengths, the array can be extended in both the X and Y directions.

Figure 10 shows the straightforward method of stacking multipliers so as to accumulate partial products and generate a resultant product.

Figure 9 diagrammatically shows the connection scheme for the 12 x 12 multiplier of Figure 10, the straightforward parallelogram structure. The longest propagation delay path is shown by the arrow. The typical propagation delay of this path is computed as shown in Table II. Note that this is not the maximum speed connection.

In the diagram of Figure 9, the shorthand notation inside the individual multiplier notation represents the "system" bit numbers connected to the y_0 and x_0 bits respectively. Thus, if the system words are A and B, 4·8 represent A_4 is connected to y_0 of that multiplier element and B_8 is connected to x_0 of that multiplier element. Remember, each individual Am25S05 is labeled y_{-1} , y_0 , y_1 , x_{-1} , x_0 , x_1 , x_2 , x_3 and x_4 . When connected in an iterative system, these inputs should be relabeled to y_{i-1} , y_i , y_{i+1} , x_{j-1} , x_j , x_{j+1} , x_{j+2} , x_{j+3} and x_{j+3} (not x_{j+4}). Then the ij nomenclature inside the element is for the subscript of the system bit numbers.

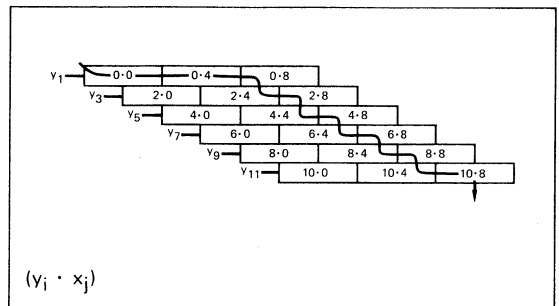


Figure 9. Diagrammatical Representation of Standard 12 x 12 Parallelogram Structure and Longest Propagation Path

TABLE II — CALCULATION OF TYPICAL PROPAGATION DELAY FOR PARALLELOGRAM 12 x 12 MULTIPLIER

	t_{PLH} Typical	t_{PHL} Typical	$\frac{t_{PLH} + t_{PHL}}{2}$
y_i to C_{n+4}	23 ns	20 ns	21.5 ns
C_n to C_{n+4}	8 ns	9 ns	8.5 ns
C_n to S_{03}	12 ns	10 ns	11.0 ns
k_i to C_{n+4}	6.5 ns	10 ns	8.25 ns
4 Additional C_n to S_{03} and k_i to C_{n+4} paths			77.0 ns
C_n to S_{45}	15 ns	13 ns	14.0 ns
		Total	140.25 ns

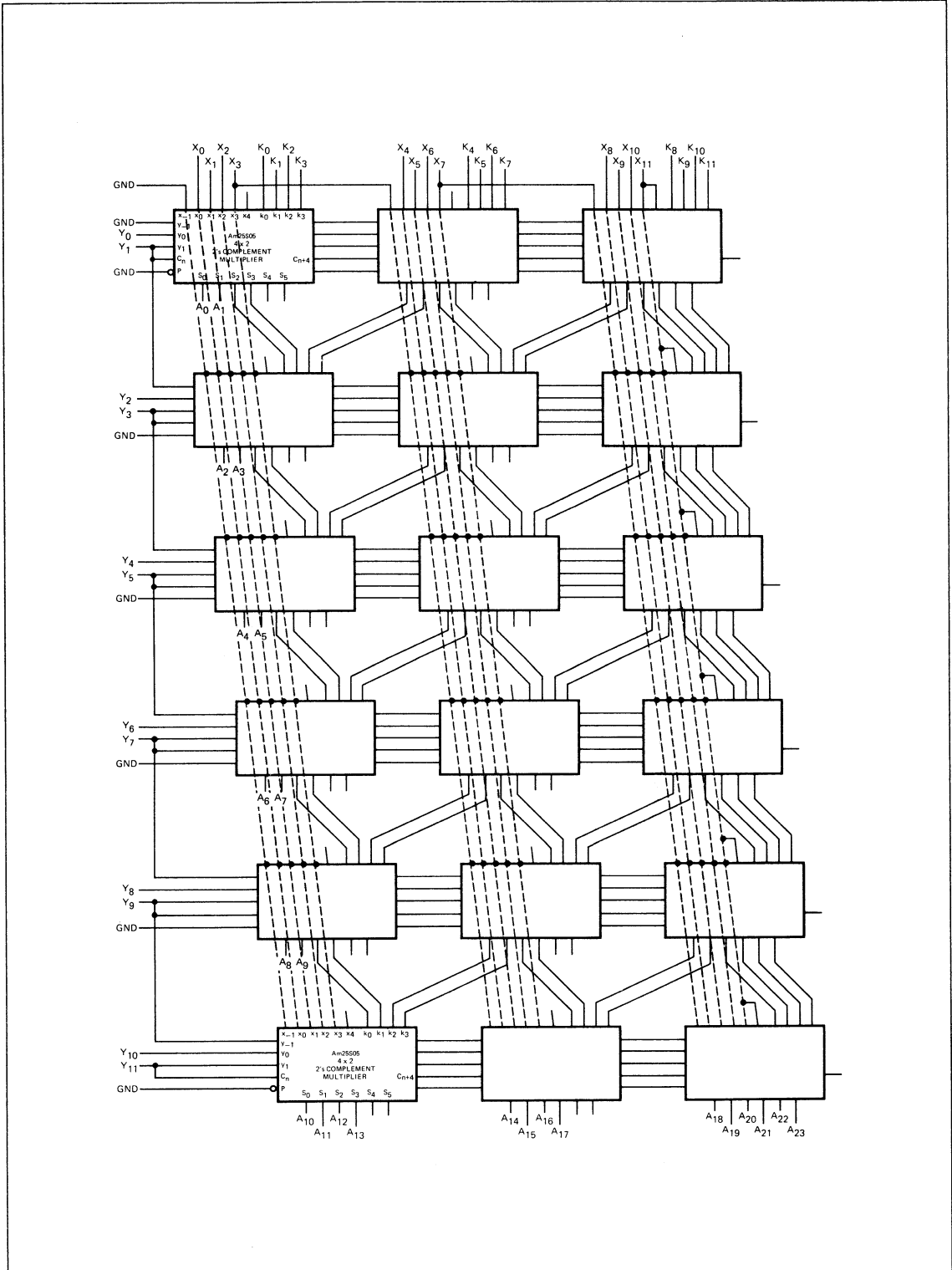


Figure 10. 12 x 12 Multiplier in Parallelogram Structure

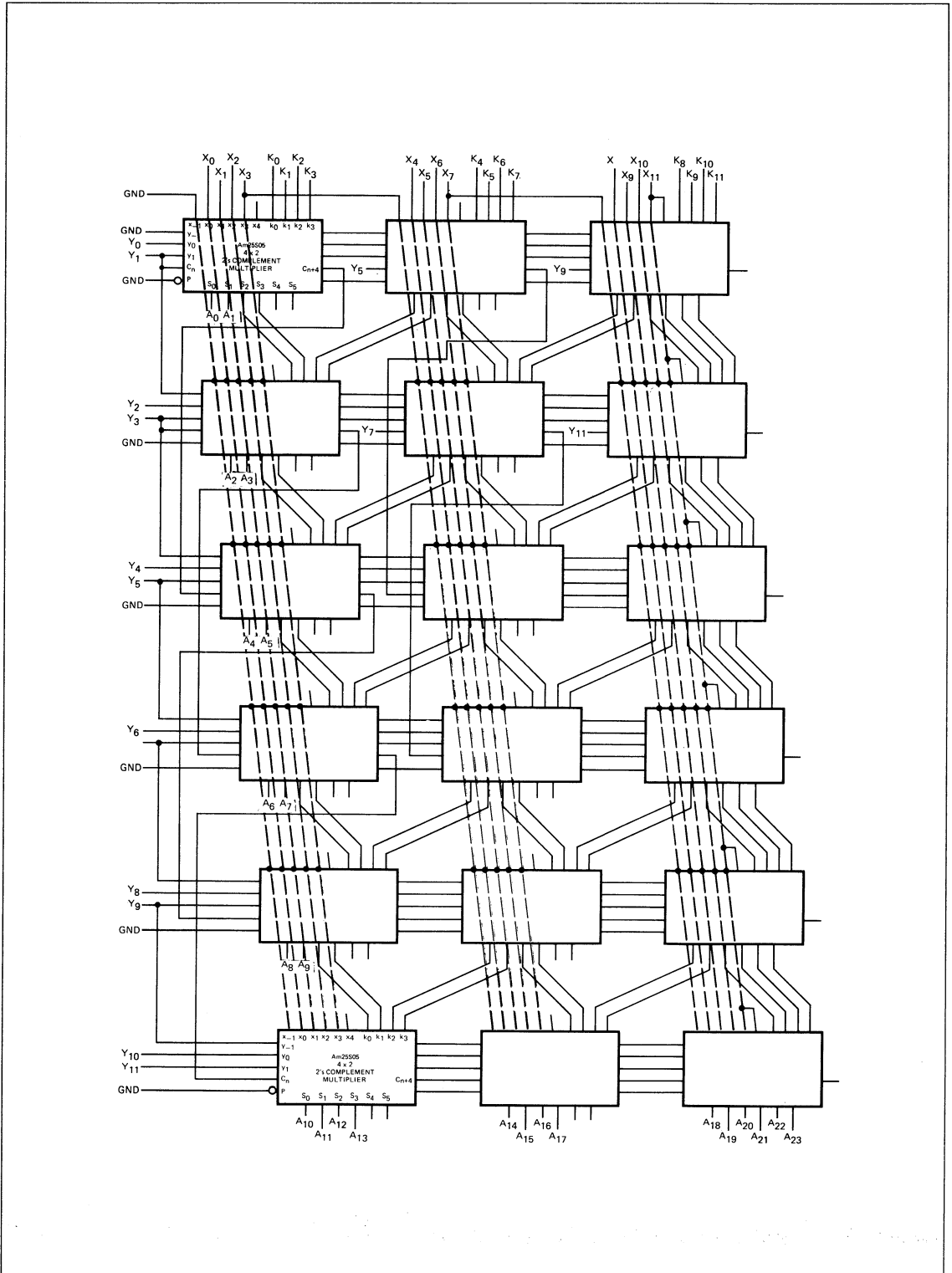


Figure 11. High Speed 12 x 12 2's Complement Multiplication

A second, faster configuration for the connection of a 12 x 12 multiplier in a parallelogram-type structure is shown in the connection diagram of Figure 11 and diagrammatically in Figure 12. The significant difference between the connection in Figure 11 and the connection in Figure 10 involves the y inputs connected to the carry inputs. Notice in Figure 10 that there are y inputs going into carry inputs down the left edge of the array to add "1" at the LSB of the partial product during subtraction. Every odd y_{i+1} goes into a carry of weight i . However, within the array there are carry signals lying in the critical speed path with the same weight as these y inputs. By interchanging some of these y inputs with carries higher up in the array, it is possible to shorten the critical speed path. For example, the carry out of the first Am25S05 has a weight of 2^4 as does the y_5 input in the third row carry in. By interchanging these two signals as shown in Figure 11, the first Am25S05 is removed from the critical speed path. The carry between the first and second devices in the second row has a weight of 2^6 and may be interchanged with the y_7 signal. This interchanging may be continued across and down the array wherever applicable. The general philosophy of this method is to equalize the delays through the array from the top to all parts of the output rather than having some output bits available very rapidly and others more slowly. The result is that the longest propagation delay path will also be decreased. Table III shows the computation for the typical propagation delay of the longest path for this connection.

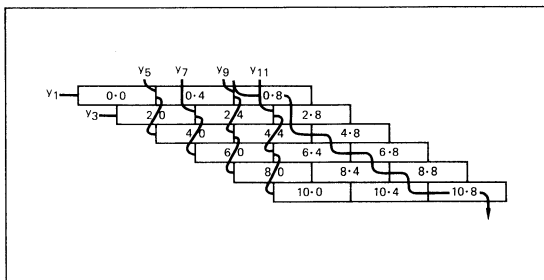


Figure 12. Diagrammatical Representation of High-Speed 12 x 12 Parallelogram Structure and Longest Propagation Path

TABLE III – CALCULATION OF TYPICAL PROPAGATION DELAY FOR 12x12 MULTIPLIER WITH CARRIES MOVED

	t_{PLH} Typical	t_{PHL} Typical	$t_{PLH} + t_{PHL}$ 2
y_i to S_{03}	23 ns	23 ns	23 ns
k_i to S_{03}	13.5 ns	9.5 ns	11.5 ns
k_i to C_{n+4}	6.5 ns	10 ns	8.25 ns
C_n to S_{03}	12 ns	10 ns	11.0 ns
2 Additional k_i to C_{n+4} and C_n to S_{03} paths	2(8.25 + 11.0)ns		38.5 ns
k_i to C_{n+4}	6.5 ns	10 ns	8.25 ns
C_n to S_{45}	15 ns	13 ns	14.0 ns
		Total	114.5 ns

A third configuration for a 12 x 12 multiplier is shown diagrammatically in Figure 13. In this structure, four of the Am25S05's have been moved vertically while maintaining the relative partial sum weights. This results in an increase in speed over the standard parallelogram structure by decreasing the maximum propagation path length. The speed of this triangular structure, Figures 13 and 15, is the same as that of the parallelogram structure with carries moved, Figures 11 and 12.

Figure 14 diagrammatically illustrates the connection scheme for 16 x 16 arrays connected in the three types of structures previously described. In each method the carry-in connection

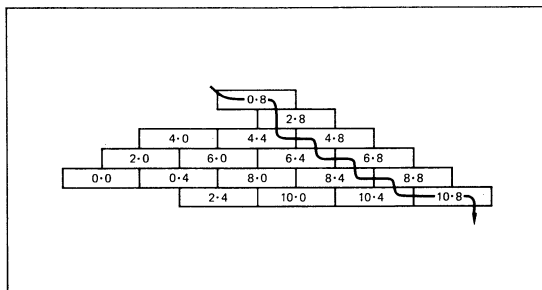


Figure 13. Diagrammatical Representation of 12 x 12 Multiplier in Triangular Array

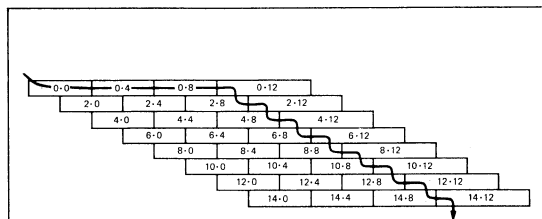


Fig.14(a)

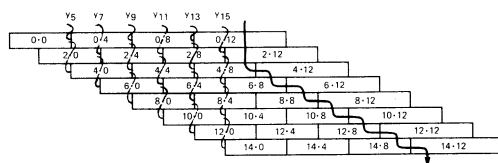


Fig.14(b)

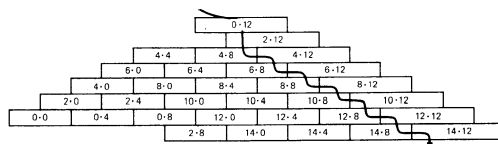


Fig.14(c)

Figure 14. 16 x 16 Multiplier Connection Schemes

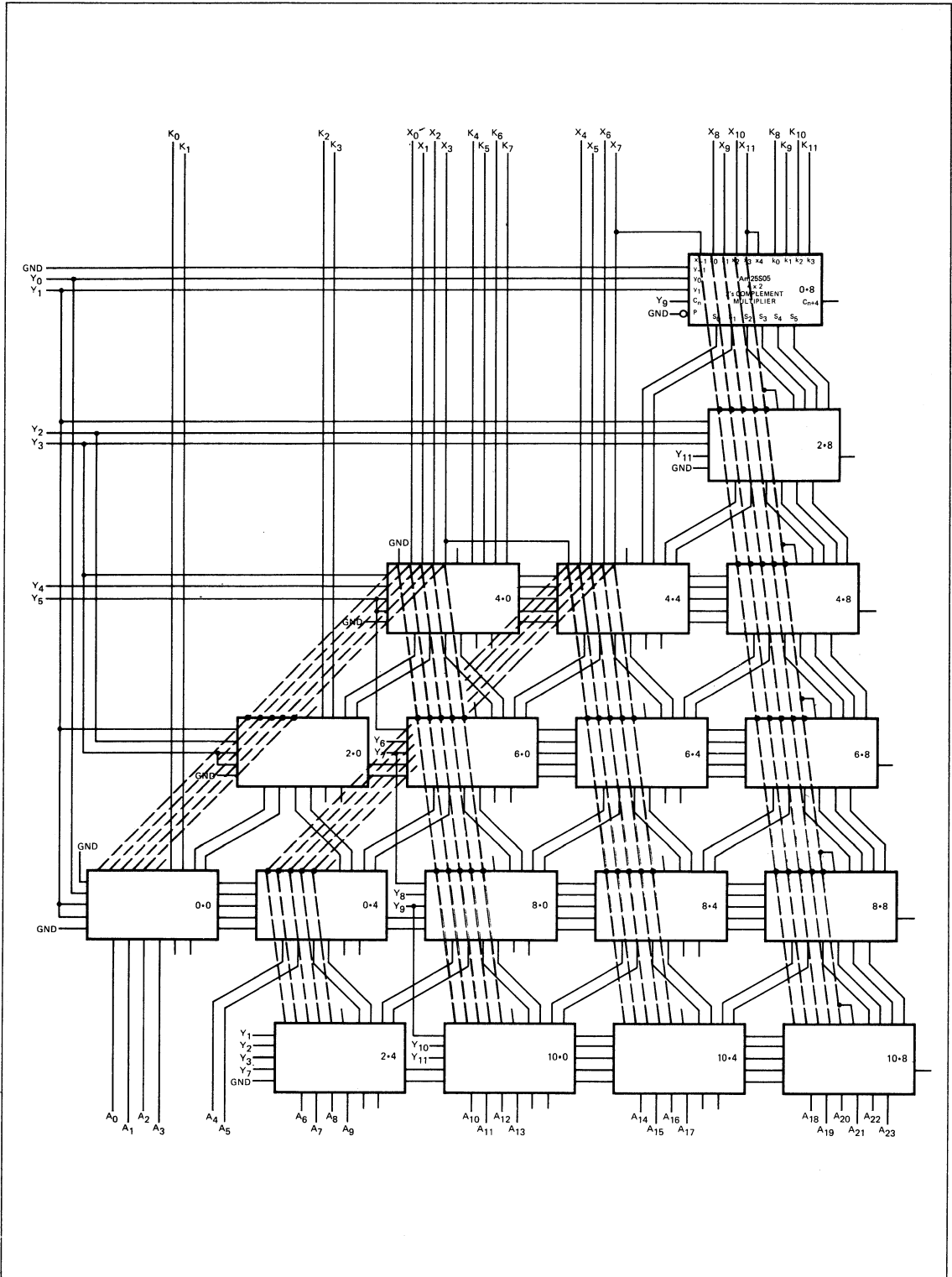


Figure 15. Connection for 12 x 12 Configuration in the Triangular Array.

TABLE IV – TYPICAL MULTIPLICATION TIME IN NANO-SECONDS.

Array Size Y x X	Number of Am25S05's	Time (ns) Method 1	Time (ns) Method 2 Method 3
4 x 4	2	39	—
4 x 8	4	55	—
4 x 12	6	64	—
8 x 8	8	94	76
8 x 12	12	102	94
8 x 16	16	111	102
12 x 12	18	141	115
12 x 16	24	149	132
12 x 20	30	157	141
16 x 16	32	188	153
16 x 20	40	196	171
16 x 24	48	205	179
20 x 20	50	235	192
20 x 24	60	243	209
20 x 28	70	251	218
24 x 24	72	282	230
24 x 28	84	290	248
24 x 32	96	299	256
28 x 28	98	329	269
28 x 32	112	337	286
32 x 32	128	376	307

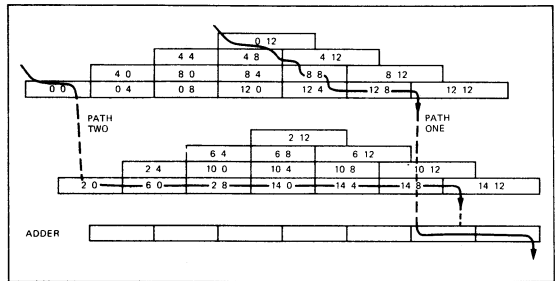
to the C_n level is shown. If no connection is shown, it is assumed that C_{n+4} is connected to the next C_n . Table IV shows the delays and package count for various size multiplier arrays using these three connection methods.

FASTER MULTIPLICATION USING ADDITIONAL ADDERS

If faster multipliers are required, the multiplication array can be split into several parts and the partial products from these parts added using high-speed carry look-ahead adders. This method results in a substantial increase in speed — especially for larger multipliers — with relatively few additional packages. One connection for a 16 x 16 multiplier using one level of additional partial product adders is shown diagrammatically in Figure 16.

This method involves breaking the array into two 8 x 16 indirectly structured arrays. The first contains all X connections and the Y connections to the 0, 1, 4, 5, 8, 9, 12 and 13 bits. The second array contains all X connections and the Y connections to the 2, 3, 6, 7, 10, 11, 14 and 15 bits. In all cases, the y_{i-1} bit is connected to the correct weight bit. For example, y_{i-1} is connected to bit 5 for $y_0 = 6$ and $y_1 = 7$. Notice that for both 8 x 16 structures, the y_{i-1} bits are cross coupled to the other array. The typical speed computation for this connection is shown in Table V.

Another connection scheme for a 16 x 16 multiplier using three additional partial product adders (two levels) is shown in Figure 17. Here, the multiplier is broken into four 4 x 16 arrays. Then the outputs of two of the arrays are combined in one high-speed adder and at the same time the outputs of the other two arrays are combined in another high speed adder.

**Figure 16. Multiplier Connection with One Level of Additional Adders****TABLE V – CRITICAL PROPAGATION DELAY PATH FOR 16 x 16 MULTIPLIER WITH ONE LEVEL OF ADDERS.**

Path One	t_{PLH} Typical	t_{PHL} Typical	$\frac{t_{PLH} + t_{PHL}}{2}$
y_i to S_03	23.0 ns	23.0 ns	23.0 ns
k_i to C_{n+4}	6.5 ns	10.0 ns	8.25 ns
C_n to S_03	12.0 ns	10.0 ns	11.0 ns
k_j to S_03	13.5 ns	9.5 ns	11.5 ns
k_j to C_{n+4}	6.5 ns	10.0 ns	8.25 ns
C_n to C_{n+4}	8.0 ns	9.0 ns	8.5 ns
C_n to S_03	12.0 ns	10.0 ns	11.0 ns
A to C_{n+4}	Am54S/74S181	Assumed	12.5 ns
C_n to F	Am54S/74S181	Assumed	7.0 ns
			Total 101.0 ns
Path Two			
y_i to S_03	23.0 ns	23.0 ns	23.0 ns
k_j to C_{n+4}	6.5 ns	10.0 ns	8.25 ns
C_n to C_{n+4}	8.0 ns	9.0 ns	8.5 ns
4 Additional	4(8.5 ns)		34.0 ns
C_n to C_{n+4}			34.0 ns
C_n to S_03	12.0 ns	10.0 ns	11.0 ns
B to C_{n+4}	Am54S/74S181	Assumed	12.5 ns
C_n to F	Am54S/74S181	Assumed	7.0 ns
			Total 104.25 ns
			~105 ns

The resultant sums of the two high speed adders are combined in a third high speed adder which gives the total multiplication result. The typical speed computation for the longest path of this connection is shown in Table VI.

The advantage of the scheme shown in Figure 17 is that about one-half of the total delay is in the external adder. A further decrease in the average multiplication time can be achieved by storing the partial sums in registers or latches, then adding the stored parts in the high speed adders. This results in a two-step time sequenced mode of operation.

TIME-SEQUENCED MULTIPLIERS

The Am25S05 can be used as the main element in a time-sequenced multiplier. This is illustrated in Figure 18. The multiplier and partial product are shifted two places after each

iteration. Three single-length registers are required: one holds the multiplicand; the other two hold the double-length product. The least significant part of this double-length register originally holds the multiplier, which is sequentially shifted out during the computation. A shift of two places is obtained by splitting the multiplier and partial product into odd and even parts and placing the odd bits in one shift register and the even bits in the other. A shift of one place of both registers then effectively acts as a shift of two places.

The scheme can be extended to use any number of even multiplier bits. As the number of bits increases, the multiplication time increases, and the amount of ancillary hardware increases. When Am25S05's are used in a combinational array, the array does not require any additional devices. Time-sequenced multipliers are worthwhile mainly if the word lengths are long or if the auxiliary registers can be shared with other arithmetic operations. This is one example of a serial-parallel multiplier.

INTEGER MULTIPLICATION

The Am25S05 can multiply 2's complement numbers in either integer or fractional form. The primary difference is in the thought process of the designer. When the binary patterns are treated as integers, the 2's complement numbers can be represented as

$$\begin{aligned}
 X &= x - x_s 2^{n-1} \\
 Y &= y - y_s 2^{m-1} \\
 K &= k - k_s 2^{p-1}
 \end{aligned}$$

where

- x_s = sign bit of X (one or zero)
- y_s = sign bit of Y (one or zero)
- k_s = sign bit of K (one or zero)
- x = magnitude bits of X (less sign)
- y = magnitude bits of Y (less sign)
- k = magnitude bits of K (less sign)
- n = number of bits in X word
- m = number of bits in Y word
- p = number of bits in K word

For example, if six bits are assumed for X, $n = 6$ and the sign bit has a weight of $-2^{6-1} = -2^5 = -32$. The other magnitude bits have their normal weight and since there are five other magnitude bits, they are $2^0, 2^1, 2^2, 2^3$, and 2^4 . Thus, 2's complement integer numbers for $n = 6$ bits are as shown below:

Integer Decimal Number Equivalent	Magnitude bits					
	-2^5 Sign	2^4	2^3	2^2	2^1	2^0
	-32	16	8	4	2	1
14	0	0	1	1	1	0
31	0	1	1	1	1	1
0	0	0	0	0	0	0
-7	1	1	1	0	0	1
-25	1	0	0	1	1	1
-32	1	0	0	0	0	0

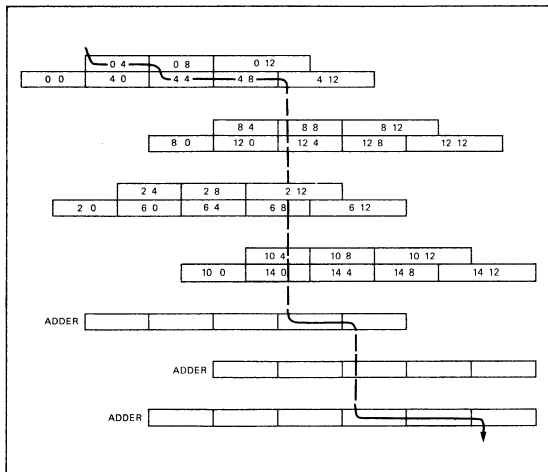


Figure 17. Multiplier Connection with Two Levels of Additional Adders

TABLE VI – CRITICAL PROPAGATION DELAY PATH FOR 16 x 16 MULTIPLIER WITH TWO LEVELS OF ADDERS

	t_{PLH} Typical	t_{PHL} Typical	$\frac{t_{PLH} + t_{PHL}}{2}$
Y_i to C_{n+4}	23.0 ns	20.0 ns	21.5 ns
C_n to S_{03}	12.0 ns	10.0 ns	11.0 ns
k_i to C_{n+4}	6.5 ns	10.0 ns	8.25 ns
C_n to C_{n+4}	8.0 ns	9.0 ns	8.5 ns
C_n to S_{03}	12.0 ns	10.0 ns	11.0 ns
A to C_{n+4}	Am54S/74S181 Assumed		12.5 ns
C_n to F	Am54S/74S181 Assumed		7.0 ns
A to C_{n+4}	Am54S/74S181 Assumed		12.5 ns
C_n to C_{n+4}	Am54S/74S181 Assumed		7.0 ns
C_n to F	Am54S/74S181 Assumed		7.0 ns
			Total 106.75 ns

When the product of X and Y is considered, the following equation results:

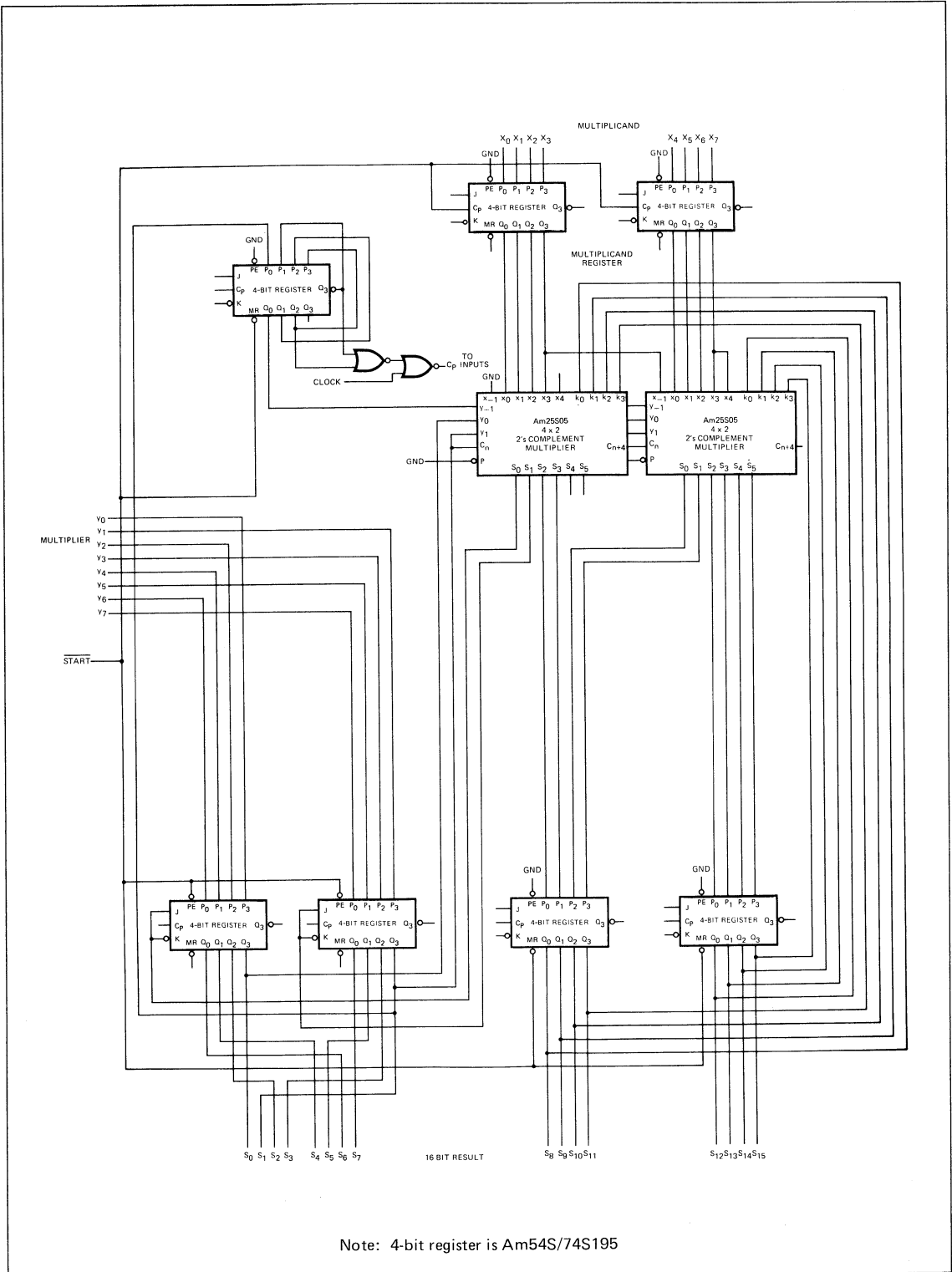
$$S = XY = x_s y_s 2^{m+n-2} - x y_s 2^{m-1} - y x_s 2^{n-1} + xy$$

The 2's complement product requires $m + n$ bits in order to represent all possibilities. Note that there is only one condition where the $m + n$ bits are required; that condition being:

$$X = -2^{n-1} \text{ and } Y = -2^{m-1}$$

This condition gives $S = XY = 2^{m+n-2}$ which requires $m + n$ digits in a 2's complement signed integer number.

Consider $n = 6$ and $m = 4$, then x_s has weight -32 and y_s has weight -8 . For $X = -32$ and $Y = -8$, the product XY is $+256$. The 2's complement representation is 010000000. Ten bits are required to properly represent the 2's complement number. All other combinations of values for X and Y require only $m + n - 1$ bits to represent the 2's complement number. For $n = 6$ and $m = 4$ in this case, the ninth bit represents the product sign. Consider $(+7) \times (-31)$ is equal to -217 or



Note: 4-bit register is Am54S/74S195

Figure 18. 8 x 8 Time Sequenced Multiplier

100100111. Notice that 1100100111, the ten bit 2's complement representation is identical in value.

The *general* requirement for the product solution of XY is:

$$S = XY = s - s_s 2^{m+n-1}$$

and all binary operations must be carried through m + n bits in the product solution unless a simplification is assumed.

In the Am25S05 (as well as the Am2505 and Am25L05), the sum output, S, of the device is:

$$S = XY + K.$$

This can be seen in Figure 6.

The devices are designed such that in an iterative array, the K inputs to the adder are available only at the initial least significant partial product input. Thus in an iterative system, the sum is defined as:

$$S = x_s y_s 2^{m+n-2} - x_s y_s 2^{m-1} - (y x_s + k_s) 2^{n-1} + xy + k$$

The k_s term can contribute at weight 2^{n-1} and the k term at weight $2^0 = 1$. Thus, m + n bits are sufficient to contain all possible values of $S = XY + K$.

FRACTIONAL MULTIPLICATION

Fractional multiplication using the Am25S05 is identical with integer multiplication but the notation is changed. The fractional number range is usually limited to $-1 \leq X \leq 1 - 2^{-(n-1)}$.

The fractional 2's complement binary numbers can be represented as:

$$\begin{aligned} X &= x 2^{-(n-1)} - x_s \\ Y &= y 2^{-(m-1)} - y_s \\ K &= k 2^{-(p-1)} - k_s \end{aligned}$$

where the notation is as with integer arithmetic. The sign bit now has a weight of $-2^0 = -1$ and the other magnitude bits have their normal fractional weight.

Two's complement numbers for n = 6 are as shown below.

Fractional Equivalent	-2 ⁰	2 ⁻¹	2 ⁻²	2 ⁻³	2 ⁻⁴	2 ⁻⁵
	-1	1/2	1/4	1/8	1/16	1/32
14/32 = 7/16	0	0	1	1	1	0
31/32	0	1	1	1	1	1
0	0	0	0	0	0	0
-7/32	1	1	1	0	0	1
-25/32	1	0	0	1	1	1
-32/32 = -1	1	0	0	0	0	0

The notation difference in the fractional representation is that all the integer representations have been divided by $2^{(n-1)}$.

The fractional product XY is

$$S = XY = x_s y_s - x_s y 2^{-(m-1)} - y_s x 2^{-(n-1)} + xy 2^{-(m+n-2)}$$

Again, m+n bits are required to cover all possible combinations. Note that X = -1 and Y = -1 results in XY = +1 which is beyond the normal range. In order to cover this possibility, the sign bit should be given a weight of -2 (instead of -1); the next most significant bit is weight +1, the next is +1/2, and so forth. If the -1 times -1 possibility is excluded only m+n-1 bits are required.

The Am25S05 used in an iterative structure produces a fractional sum $S = XY + K$, but the K inputs are now at the same weight as the least significant partial product inputs. Thus $K = k 2^{-(m+n-2)} - k_s 2^{-(m-1)}$. The sum is:

$$S = XY + K = x_s y x - (x_s y + k_s) 2^{-(m-1)} - y_s x 2^{-(n-1)} + (xy + k) 2^{-(m+n-2)}$$

This general equation requires the sign bit to have a weight of -2 and all arithmetic to be carried to m+n bits to represent the two's complement solution.

In conventional minicomputer 2's complement multiplication of fractional numbers, the product, S, has only m+n-1 bits and is constrained in the range of $-1 \leq S \leq 1 - 2^{-(m+n-2)}$ with the most significant bit (sign bit) having a weight of -1. Outside of this range, an overflow indication is given. The Am25S05 produces a product of m+n digits so that all product results XY+K are correctly represented and the sign bit has weight -2. Notice that if K = 0 (the condition in conventional machine multiplication), m+n digits are required only for X = Y = -1. Thus if S is used with m+n-1 bits, the most significant bit of the Am25S05 array can be ignored, and an overflow indication can be generated by $S_{-2} \oplus S_{+1}$ ($S_5 \oplus S_4$ on the most significant Am25S05 output).

In fractional notation, the K inputs add to the least significant end of the adder. If K is negative, the k_s bit is in effect repeated completely across the most significant part of the product via the x_4 input and S_4 and S_5 outputs. If a double length K addition is required, an adder can be appended to the most significant part of the product with the carry-in terminal connected to k_s so that the "1"s across the most significant part of the product are removed and the desired most significant bits added. Figure 19 shows a 4 x 4 multiplication with double length addition while Figure 20 shows numeric examples of 4 x 4 multiplications.

In the connection scheme of Figure 19, an Am25S05 has been used as an adder to provide the desired overflow operation at the most significant end of the word. With the y input connection shown, the adder performs $S = X$ plus K with the S_4 output correct for this 2's complement number range. The S_5 output is not used. If K is limited to the range of $-1/8 \leq K \leq \frac{63}{64}$, an adder such as the Am54S/74S181 or Am54S/74S283 can be used to perform the addition of the most significant K bits. In this case only 8 bits will be required to represent the product and it will be in the range of $-2 \leq S \leq 1 \frac{63}{64}$.

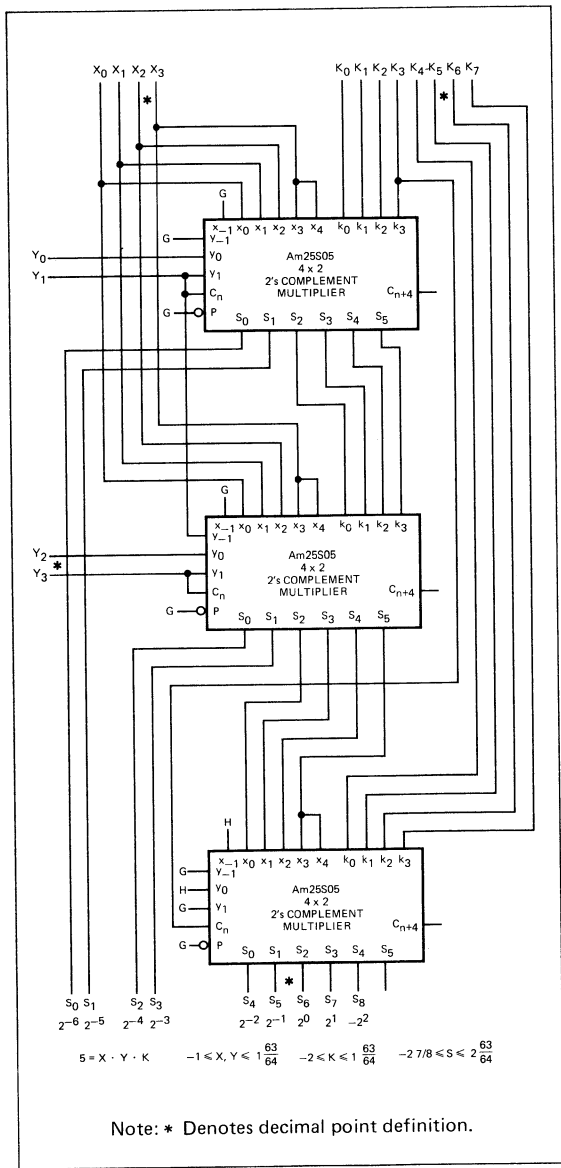


Figure 19. 4 x 4 Fractional Double Length Multiplication and Addition.

ROUND-OFF

It is often convenient to use only the most significant half of a product. This product should be rounded off; that is, it should approximate the best n-bit answer possible. This can be done by examining the least significant half of the product, and if it is greater than or equal to a certain value, (normally 1/2 that of the least significant digit of the truncated product) adding a '1' to its most significant position.

Forming a rounded t-bit product from a conventional product constrained within the range $-1 \leq S \leq 1 - 2^{-(m+n-2)}$ can be accomplished by adding a '1' to the K input at weight

OVER-FLOW	-1	1/2	1/4	1/8	1/16	1/32	1/64	Fractional value
Example #1								
X	0	1	0	1				5/8
Y	0	0	1	1				3/8
XY	0	0	0	0	1	1	1	15/64
+K	0	0	0	0	0	0	1	3/64
Sign extended via k_s								
XY+K	0	0	0	1	0	0	1	18/64
Example #2								
X	1	0	0	0				-7/8
Y	0	1	0	0				1/2
XY	1	1	1	0	0	1	0	-28/64
+K	1	1	1	1	1	1	1	-1/64
Sign extended via k_s								
XY+K	1	1	1	0	0	0	1	-29/64
Example #3								
X	1	1	0	1				-3/8
Y	1	0	0	1				-7/8
XY	0	0	0	1	0	1	0	1
+K	0	0	0	0	0	0	0	0
Sign extended via k_s								
XY+K	0	0	0	1	0	1	0	1

Figure 20. Three Examples of Two's Complement 4 x 4 Multiplications

2^{-t} . For the case where $t = m = n$, this is one k position lower than the K sign digit. An example of rounding for $t = m = n = 4$ is shown below.

$$\begin{aligned}
 X &= 0.0111 &&= 3/8 \\
 Y &= 0.101 &&= 5/8 \\
 XY &= 00.001111 &&= 15/64 \\
 +K &= 00.000100 \\
 S &= 00.010011
 \end{aligned}$$

Rounded t-bit product from the 2t-bit product is

$$S = 0.010 = 1/4$$

For the case $m = 4$ and $n = 8$, the sum of $m+n$ is 12. If a six bit rounded product is desired, a "1" is added at weight 2^{-6} . If an eight bit rounded product is desired, a one is added at weight 2^{-8} .

If the sum output is not constrained as before but covers the range $-2 \leq S \leq 2 - 2^{-(m+n-2)}$, care must be taken when rounding. For the case where $m = n$ is rounded to m (or n) bits the "1" is to be added at the k_s (sign) weight. The multiplier would treat this as a negative k_s sign bit and it would be extended up through the array most significant bit. Therefore, this connection cannot be made. It is recommended that for this case, the k_s sign bit be connected to logic "0" and all lower order k bits be connected to logic "1". This comes very near the desired rounding criteria; otherwise an additional adder is required at the output to add a one at the k_s weight only.



TABLE VII – WORST CASE EFFECT OF TRUNCATION BY REMOVING MULTIPLIERS

12 bit LSB		Truncated Bits											Multiplier removed	
2 ¹³	2 ¹²	2 ¹¹	2 ¹⁰	2 ⁹	2 ⁸	2 ⁷	2 ⁶	2 ⁵	2 ⁴	2 ³	2 ²	2 ¹		2 ⁰
14	13	12	11	10	9	8	7	6	5	4	3	2		1
							1	1	1	1	1	1	1	0-0 removed 2-0 removed
						1	0	0	1	1	0	1	1	effect 0-4 removed
				1	0	0	1	1	1	1	0	1	1	effect 4-0 removed
			1	0	0	0	1	1	0	1	0	1	1	effect 2-4 removed
		1	0	1	1	1	1	1	0	1	0	1	1	effect 6-0 removed
1		0	0	1	1	1	0	1	0	1	0	1	1	effect

TRUNCATION

If the user is prepared to accept a truncated product where the product is incorrect by some fraction of a least significant digit, the number of IC's required for the multiplication can be reduced. The designer can determine the accuracy required for his application and remove packages as long as the error does not exceed the desired accuracy.

A simple procedure for examining the effects of removing each Am25S05 is as follows. Each 4 x 2 multiplier can effect 5 bits of the output partial product by its S₀, S₁, S₂, S₃, and C_{n+4} output. As each package is removed, the effect on each bit level can be evaluated by summing the total bits involved.

This is best shown by an example. Assume a 12 x 12 multiplier with a 24-bit result (Reference Figure 12). When the 0-0 multiplier (yx) is removed, the 5 LSB's are effected. If the 2-0 multiplier is removed, then the first eight LSB's are effected as shown in Table VII. If the 0-4 multiplier is also removed, then two multipliers have been removed from row one and one multiplier from row two. Only the first nine bits of row one can be effected by the removal of two multipliers. Since C_{n+4} of 0-0 was considered before, the S₀ bit of 0-4 cannot be added a second time. Therefore, when the 0-4 multiplier is removed, only the S₁, S₂, S₃ and C_{n+4} bits effect the result. This is shown in Table VII by cancelling the S₀ bit of "0-4 removed". When the 4-0 multiplier is removed from row 3 the S₀, S₁, S₂, S₃ and C_{n+4} bits effect the result. When the 2-4 multiplier is removed from row 2, the S₀ bit cannot be considered.

Thus, from Table VII it can be seen that when 0-0, 2-0, 0-4, 4-0 and 2-4 are removed, the first 12 LSB's are effected and the 12 bit sum output will be accurate to about 3/4 LSB at this point. Thus, 5 multiplier packages can be removed from a 12 x 12 multiplier and maintain a 3/4 LSB accuracy. Note that 18 devices are required for full accuracy. If the 6-0 multiplier

is removed from row 4, the 12-bit result will be accurate to about 1 LSB, but only 12 devices are required rather than 18.

One further note on truncation; when a binary word is truncated, the accuracy is not ±1 LSB or ±1/2 LSB, etc. The truncated result can never increase the magnitude of the LSB because this would include rounding. Thus, a truncated result is always the sum, S, plus zero magnitude of the LSB and minus 1, 1/2 or 1/4 (or any other number) LSB. The magnitude always becomes more negative for either positive or negative numbers.

From this discussion, it should be apparent that the designer can remove packages and truncate the product to any desired bit length and accuracy. When the product is truncated, no speed increase usually occurs, since the removed multipliers are not in the longest critical speed path. This assumes that the highest speed connection is being used.

MULTIPLICATION IN OTHER NUMBER REPRESENTATIONS

Although 2's complement multiplication is the one most widely used, multiplication in other number representations often must be performed. The Am25S05 can be used to perform these multiplications if appropriate care is used and the proper connections are made.

UNSIGNED (Magnitude-only) MULTIPLICATION

The most straightforward technique to perform magnitude-only multiplication is to generate two "always positive" two's complement numbers. This is accomplished by adding a logic "0" as the most significant bit of each word, thereby generating a positive sign bit. This increases both the X and Y word lengths by one bit. The Am25S05 can be used "as is" to perform this multiplication and the two most significant multiplier

sum bits are ignored. Thus, if $m = 4$ and $n = 6$ in a magnitude-only representation, a 5×7 multiplier configuration is required. The two MSB's of the 12-bit sum are ignored which result in a 10-bit product solution in a magnitude-only representation. Note that the multiplier still performs $XY + K$ and $m + n$ bits are sufficient to contain all possibilities. (A 6×8 connection is actually used).

A second technique for unsigned multiplication also requires extending the word length one bit, but need not require a larger array. A logic "0" is appended to each word as a positive sign bit; then the LSB of each word is considered separately.

$$X_e = x_0 + 2x - x_s 2^n$$

$$Y_e = y_0 + 2y - y_s 2^m$$

Since $x_s = y_s = 0$, the extended product is

$$X_e Y_e = 4xy + 2xy_0 + 2yx_0 + x_0 y_0$$

A n -bit by m -bit multiplier array can be used to generate $4xy$ and a conditional adder can be used to generate $2xy_0 + 2yx_0$. The term from this adder can be added to the multiplier array at the K input. The 1, 2 and 4 show the proper weighting for each term. The term $x_0 y_0$ is just an AND function and cannot produce a carry output. The first stage of the conditional adder produces the first bit of the product. The remaining product digits are produced at the output of the multiplier array. The sign digits x_s , y_s and k_s are held at logic 0 and the two most significant multiplier sum bits are ignored. The advantage of this connection is that the conditional adder is connected to the K inputs and in some cases the total multiplication time may be faster than if the above method is used.

It should also be noted that depending on the word lengths being used, it may only be necessary to extend one of the input words (X or Y) beyond the iterative array convenient length. Then it may be possible to use the K inputs as most of the conditional adder.

SIGN-MAGNITUDE MULTIPLICATION

The most straightforward technique for performing sign magnitude multiplication is to split the sign from the magnitude and perform the magnitude multiplication as described in the magnitude-only section. The sum sign bit is $s_s = x_s \bar{y}_s + \bar{x}_s y_s = x_s \oplus y_s$, which can be performed in an external exclusive-OR circuit. Note that for a sign magnitude notation, $m = 5$ and $n = 7$ only $m+n-1 = 11$ bits are needed for the sign-magnitude XY product. **Caution** — care must be taken when using the K inputs because a negative product plus K may be positive and no provision is made for this in the sign bit representation.

The notation used for a sign-magnitude word is:

$$X_{sm} = x(1-2x_s)$$

$$Y_{sm} = y(1-2y_s)$$

The $X_{sm} Y_{sm}$ product is $S_{sm} = X_{sm} Y_{sm} = xy(1-2x_s)(1-2y_s) = xy(1-2x_s-2y_s+4x_s y_s)$

The Am25S05 2's complement multiplier produces the product: $S = XY = x_s y_s 2^{m+n-2} - x y_s 2^{m-1} - y x_s 2^{n-1} + xy$

The resulting solution for the sign magnitude multiplication if the signs are included in the Am25S05 connection is

$$S_{sm} = (XY - x_s y_s 2^{m+n-2} + x y_s 2^{m-1} + y x_s 2^{n-1}) \\ (1-2x_s-2y_s+4x_s y_s)$$

There are four conditions for $x_s y_s$ and the correction required in each case is as shown below:

$x_s y_s$	XY_{sm}	
00	XY	(no correction)
10	$-XY - y 2^{n-1}$	
01	$-XY - x 2^{m-1}$	
11	$XY - 2^{m+n-2} + x 2^{m-1} + y 2^{n-1}$	

Since the terms to be added begin at weight 2^{m-1} , 2^{n-1} or 2^{m+n-2} , they must operate on the most significant part of the product. Therefore, additional adders are required at the output to make the proper connection. The technique of keeping the sign bits separate from the multiplier array and setting $K = 0$ is recommended.

ONE'S COMPLEMENT MULTIPLICATION

One's complement multiplication does not have a straightforward method as do unsigned or sign-magnitude multiplication schemes. The notation used to represent a 1's complement number is

$$X_1 = x - x_s (2^{n-1} - 1)$$

$$Y_1 = y - y_s (2^{m-1} - 1)$$

$$S_1 = X_1 Y_1 = xy + x y_s (1-2^{m-1}) + y x_s (1-2^{n-1}) + x_s y_s (1-2^{n-1} - 2^{m-1} + 2^{m+n-2})$$

If the X and Y word length are the same, then $m = n$ and the product reduces to:

$$S_1 = X_1 Y_1 = xy + (x y_s + y x_s)(1-2^{n-1}) + x_s y_s (1-2^n + 2^{2n-2})$$

The Am25S05 product for $m = n$ is

$$XY = x_s y_s 2^{2n-2} - (x y_s + y x_s) 2^{n-1} + xy$$

Remembering the definitions for X and Y in 2's complement, the solution for the one's complement multiplication sum for $m = n$ is

$$S_1 = XY + x y_s + y x_s + x_s y_s (1-2 \cdot 2^{n-1})$$

$$S_1 = XY + x_s Y + y_s X + x_s y_s$$

Note that the one's complement word relates to the two's complement word as

$$X_1 = X + x_s$$

$$Y_1 = Y + y_s$$

Therefore, the one's complement solution can also be given as

$$S_1 = XY + x_s Y_1 + y_s X_1 - x_s y_s$$

The four conditions for $x_s y_s$ with $m = n$ are:

$x_s y_s$	$X_1 Y_1$ Result Correction Requires 2's Complement Inputs and 2's Complement Addition	$X_1 Y_1$ Result Correction Requires 1's Complement Inputs and 1's Complement Addition	$X_1 Y_1$ Result Correction Requires 1's Complement Inputs and 2's Complement Addition
00	XY	XY	XY
10	$XY + Y$	$XY + Y_1$	$XY + Y_1 - 1$
01	$XY + X$	$XY + X_1$	$XY + X_1 - 1$
11	$XY + X + Y + 1$	$XY + X_1 + Y_1 - 1$	$XY + X_1 + Y_1 + 1$

Since the correction to be added is at weight $2^0 = 1$, the K inputs can conveniently be used for this purpose. Note that two designs have been described. The first requires having both one's complement numbers X_1 and Y_1 available converted to 2's complement numbers X and Y. The second requires only one's complement numbers but requires an addition of -1 (in one's complement notation). Thus, a conditional adder can be used to produce $x_s Y_1 + y_s X_1 - x_s y_s$, and the sum can be added to the multiplier at the K inputs.

If m is not equal to n, then the product $X_1 Y_1$, using the Am25S05 is $S_1 = X_1 Y_1 = XY + x_s y_s + y_s x_s + x_s y_s (1 - 2^{n-1} - 2^m - 1)$. Note that the same type of solution is possible as with $m = n$. $S_1 = X_1 Y_1 = XY + y_s X_1 + x_s Y_1 - x_s y_s$.

Thus, a conditional adder can be used and the solution is identical with the four conditions shown for $x_s y_s$ when $m = n$. The only difference is that the adder will use the m and n word lengths which must be extended sufficiently to cause repetition of the sign bit across the multipliers array.

THE y_{-1} BIT

It has been stated repeatedly that the multiplier array performs the function $S = XY + K$. This result assumes that the y_{-1} system bit is held at zero. If y_{-1} is held at logic "1", the array function becomes $S = XY + K + X = X(Y+1) + K$ which may be expanded to include y_{-1} as $S = XY + K + y_{-1} X = X(Y + y_{-1}) + K$ where y_{-1} is either logic 1 or 0. There are some applications of the multiplier array that can take advantage of this ability to add X to the product XY.

APPLICATIONS

The multiplier is ideal for hardware multiplication in general and special purpose computers, digital filter circuits, Fast Fourier Transform (FFT) processors, and special purpose digital machines. In the applications described in the following figures, the multiplier array is shown as a box which performs the function $S = XY + K$. Care must be exercised in scaling the numbers appropriately. Likewise, various other registers and adders are assumed to have a word length sufficient to handle the accuracy and magnification required. Figure 21 shows two multiplier arrays connected to generate a quadratic in x. This can be extended to form polynomials with higher powers of x.

A multiplier array connected to perform higher order polynomial evaluation in a time sequenced mode is shown in Figure 22. Note that the output register is initialized to 0 and the constants sequentially applied to the K input.

Figure 23 shows a single-pole, low-pass, recursive digital filter. The z-plane pole location is at $z = C$ where C is a constant. The register is used as the unit time delay operator z^{-1} . The K inputs can be used for the least significant bits of the data

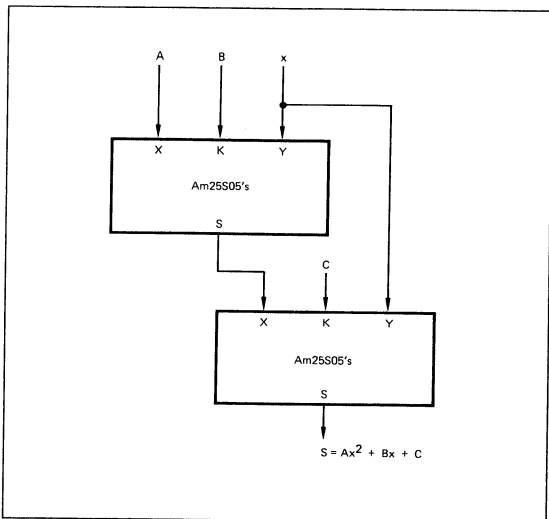


Figure 21. Polynomial Evaluation

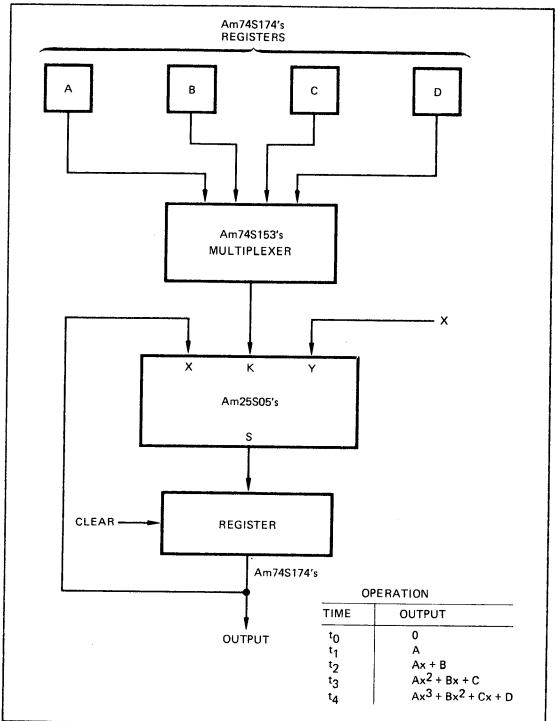


Figure 22. Time Sequenced Polynomial Evaluation

input E_i . In some designs, only the K input bits are required for the entire E_i input word. The DC gain at $z = +1$ is $1/(1-C)$.

A single pole, high-pass recursive digital filter is shown in Figure 24. The z -plane pole location is at $z = C$. Note the z -plane zero at $z = 1$ which results in a DC gain of 0, i.e., a high-pass filter.

A two-pole, low-pass recursive digital filter of canonical form is shown in Figure 25. This block produces a complex conjugate pair of poles in the z -plane when $|4D| > |C^2|$. The pole

locations are $z_1, z_2 = \frac{C}{2} \pm j\sqrt{|C^2 - 4D|}$. This configuration can

be used as a two-pole building block in more complex Butterworth or Chebychev filters. The DC gain is $1/(1-C+D)$. This value is usually very close to the peak internal-build up which occurs at a frequency just below the filter break frequency. Also shown is the case in which the input word length has been extended to full length.

Figure 26 shows a general two-pole, two-zero recursive canonical structure. By appropriately selecting the $A, B, C,$ and D constants in this configuration, the building block can be used as a high-pass, low-pass, or band-pass digital filter. The DC gain is $(1+A+B)/(1-C+D)$. The pole locations are the same as for Figure 24. The zero pair will be complex if A is negative and $|4B| > |A^2|$. If $A = -2$ and $B = 1$, then the zeros are at $(z-1)^2$ and a two-pole, high-pass filter results.

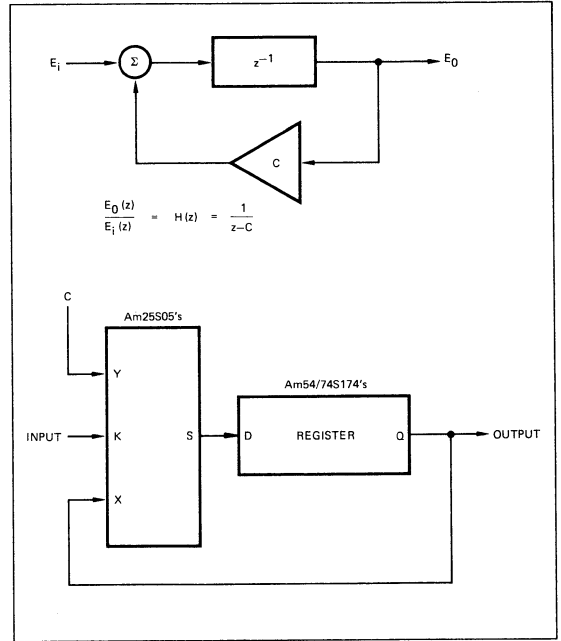


Figure 23. Single-Pole, Low Pass Recursive Digital Filter

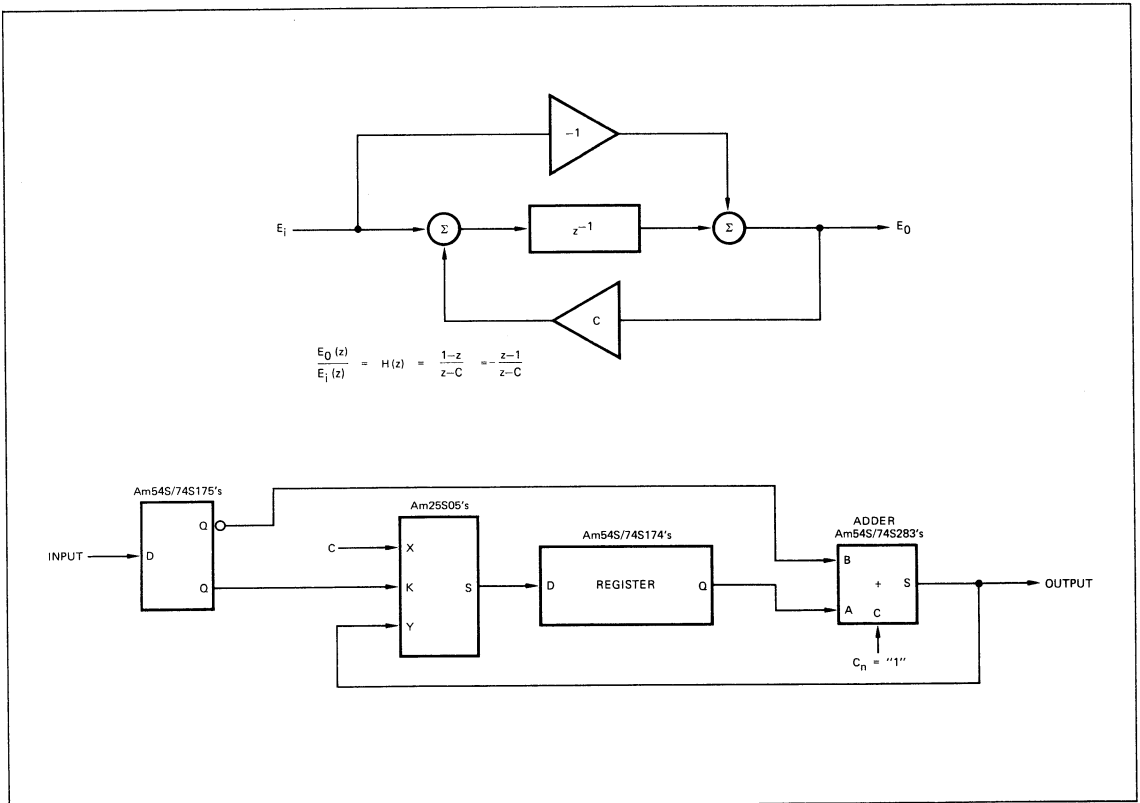


Figure 24. Single-pole, High-pass Recursive Digital Filter.

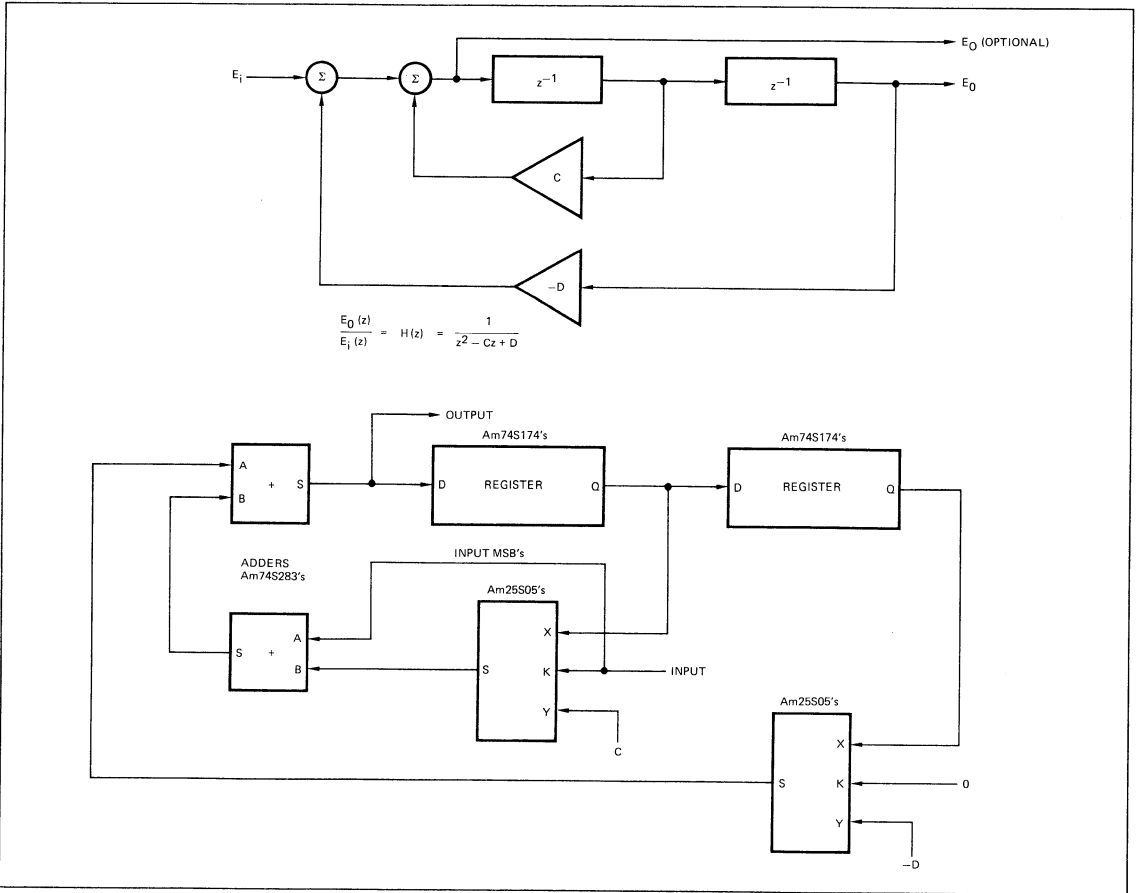


Figure 25. Two-pole, Low-pass Recursive Digital Filter

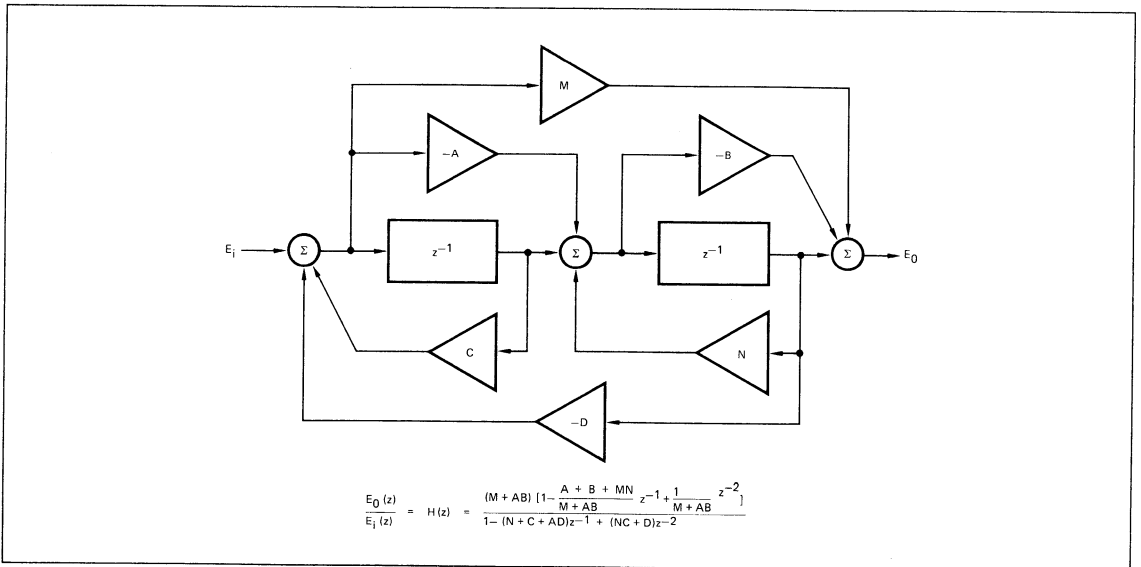


Figure 27. General Two-pole, Two-zero Recursive Digital Filter Building Block

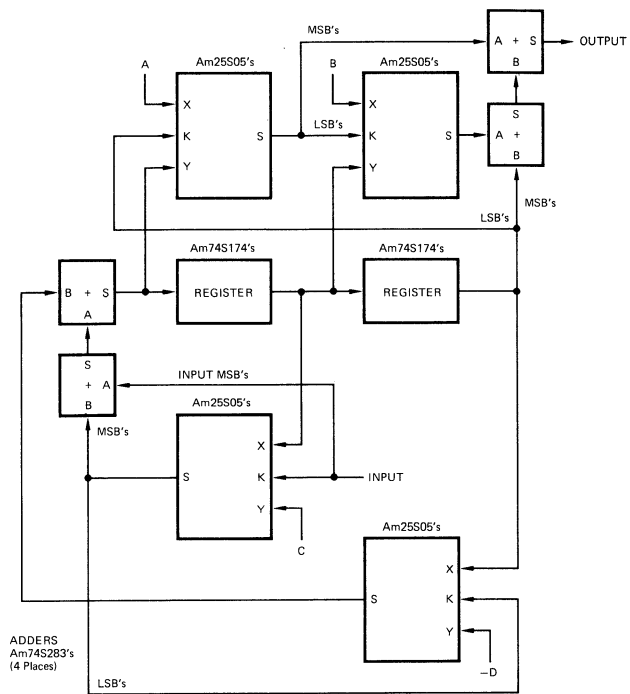
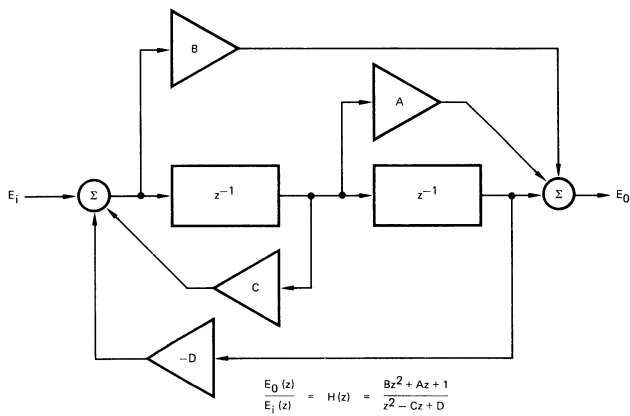


Figure 26. Canonical Two-pole, Two-zero Recursive Digital Filter.

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A general two-pole building block is shown in Figure 27. There are several options for arranging the multipliers and adders depending on the application. The z-plane transfer function is also shown in Figure 27. The multiplier constants locate the poles and zeros of the filter. Also, the internal characteristics of the filter can be adjusted using the constants.

In all of the digital filter examples shown, the single unit delay register, z^{-1} , can be replaced with multi-word registers. Thus, the arithmetic structure can be time shared by sequentially changing the multiplier constants. Also, such things as comb filters or range-gated filters can be designed using long word length registers. Remember, however, that each pole implemented requires one memory word and no sharing is possible. A non-recursive digital filter is shown in Figure 28. These structures are useful as equalizers and for certain filter applications. These structures have a finite transient response whereas the recursive filter transient response tends to be infinite.

This same non-recursive structure can be implemented as shown in Figure 29. Here one multiplier and one register are used in a time-sequenced mode. Thus, with the non-recursive structure, both the multipliers and memory may be time shared. The coefficients A, B, C, etc., are evaluated by determining the transient response of the filter desired and implementing the z-transform constants as the multiplier constants. As shown, each constant is stored in a separate register and then multiplexed to the multiplier. This may be more convenient for adaptive filters. Otherwise, the constants can be stored in a shift register that is connected to the Y input of the multiplier.

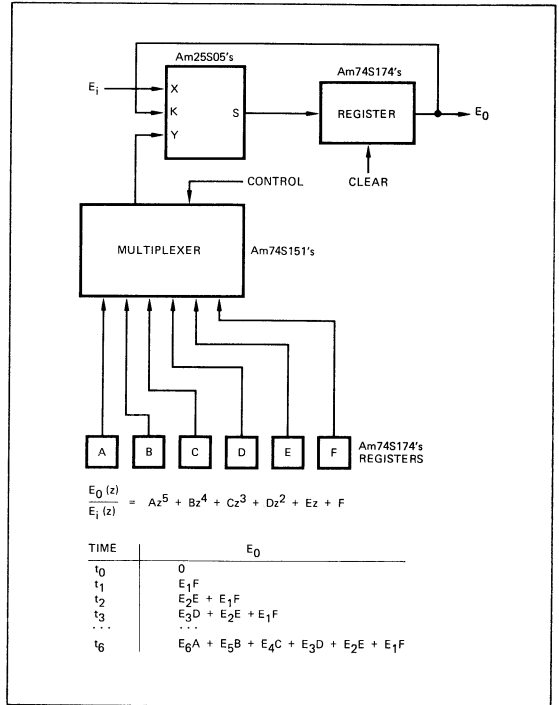


Figure 29. Time Sequenced Non Recursive Digital Filter

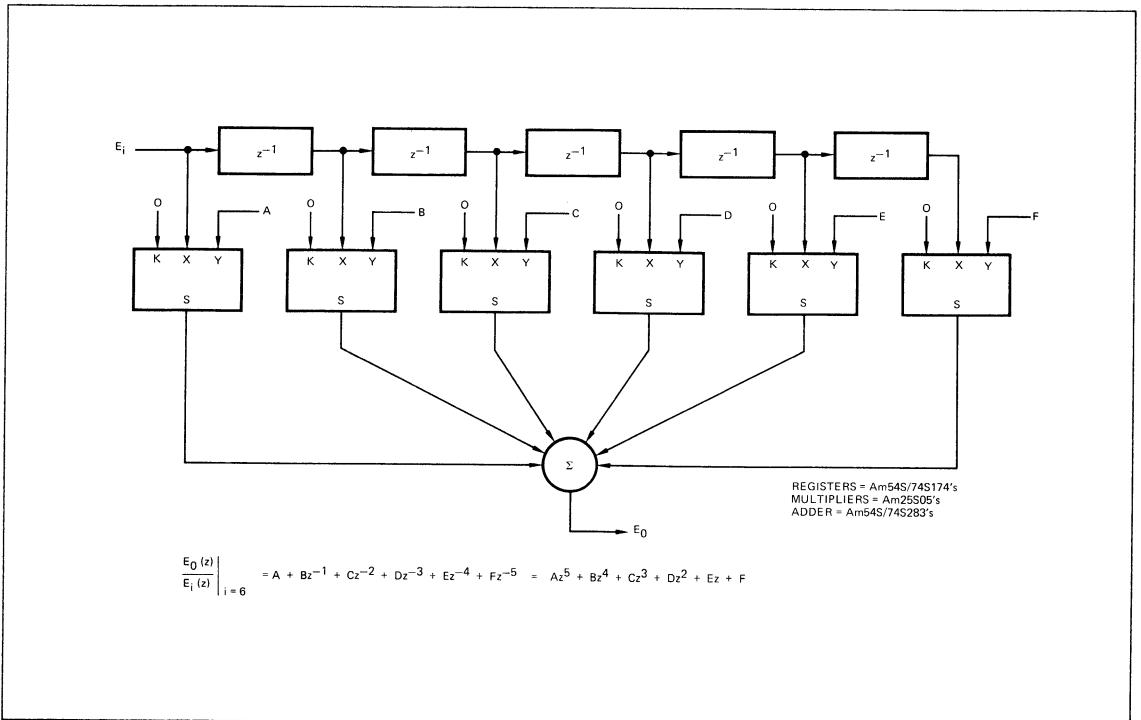


Figure 28. Non-recursive Digital Filter

Figure 30 shows how the square root of a number is formed using a multiplier array built with Am25S05 digital multipliers as the function generator. The successive approximation registers provide the estimate that is then squared and compared with the number whose root is required. If the square of the trial value is less than the number whose root is desired, then a "1" is fed back to change the register bit under consideration. The time to achieve a square root is essentially $n+1$ multiply times. The network can easily be modified to perform operations of the type $r = (X^2 + Y^2 + Z^2)^{1/2}$. The multiplier array can be used to generate the various squares, add the products and then compare the result against a trial value derived from the same multiplier array. The time required would then be $n+4$ multiplication times.

Another application frequently used is the division operation. This can be performed by multiplying the trial value, n , by the divisor and comparing the result against the dividend. If the dividend is larger than the trial value has to be increased; if the dividend is smaller then the trial value has to be reduced. The operation is fairly straightforward for unsigned division; with signed division a few problems occur.

For 2's complement integer division the logic is shown in Figure 31.

The divisor, dividend and trial quotient are all treated as 2's complement numbers. The first trial value is all ones (-1).

The operations performed are:

For Q_5 , the sign digit of the quotient:

$$\text{If } D_7 = 0 \text{ and } -\frac{D}{2} < P \text{ Set } Q_5 = 0 \text{ Otherwise } Q_5 = 1$$

$$\text{If } D_7 = 1 \text{ and } -\frac{D}{2} < P \text{ Set } Q_5 = 1 \text{ Otherwise } Q_5 = 0$$

For the remaining quotient digits:

$$\text{If } D_7 = 0 \text{ and } T_{i-1} D + \frac{D}{2} < P \text{ Set } Q_i = 1 \text{ Otherwise } Q_i = 0$$

$$\text{If } D_7 = 1 \text{ and } T_{i-1} D + \frac{D}{2} < P \text{ Set } Q_i = 0 \text{ Otherwise } Q_i = 1$$

where T_i is the i th trial value held in the SAR.

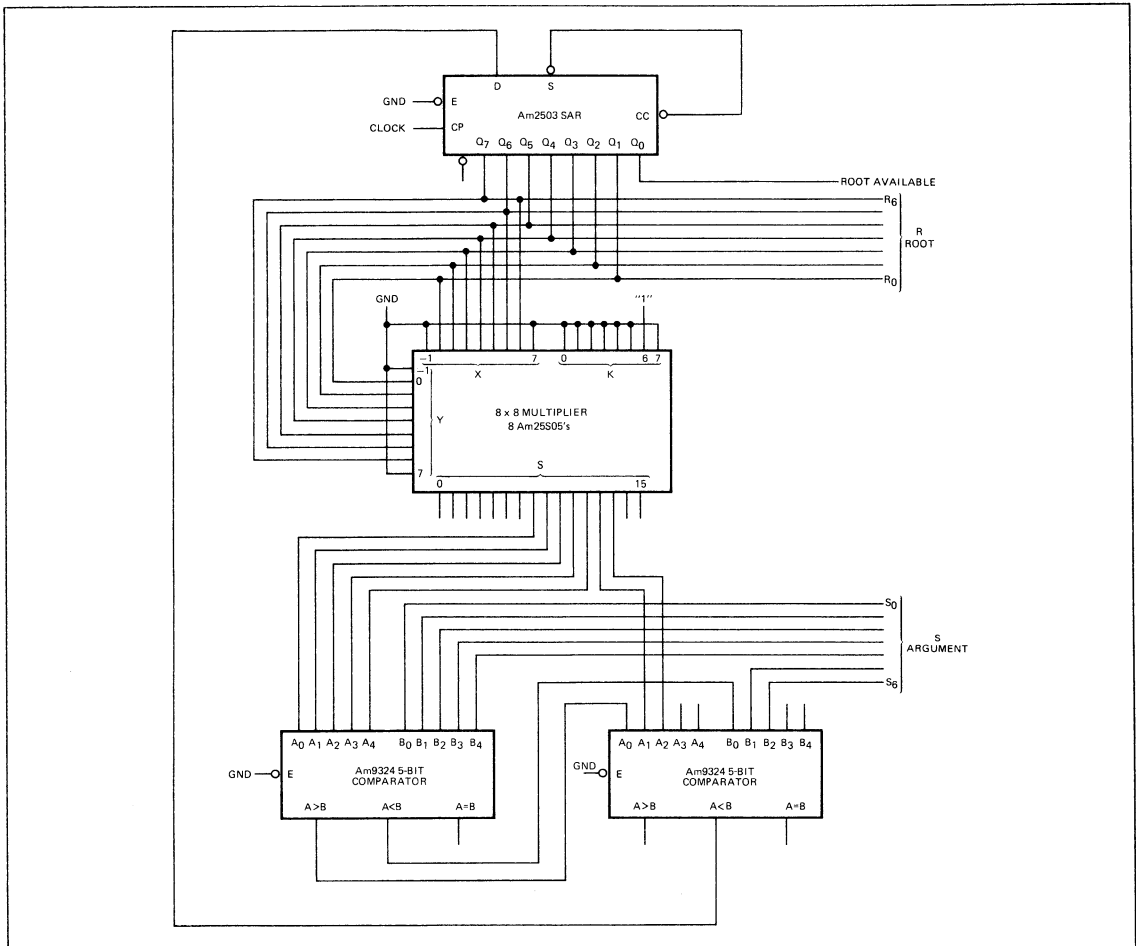


Figure 30. Square Root Evaluation by Recursion

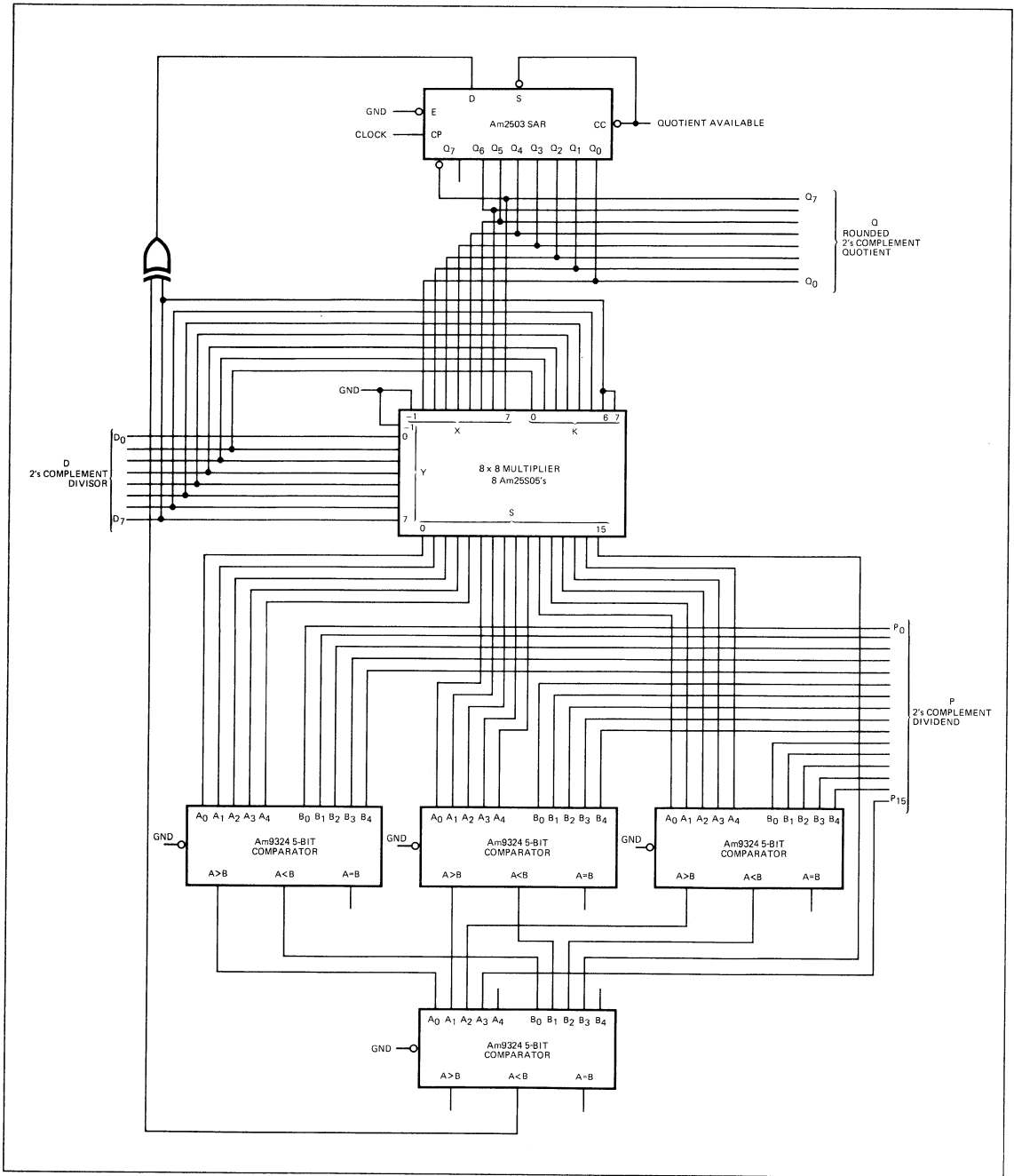


Figure 31. 2's Complement Rounded Division

Since the complement of the most significant bit of the register is used rather than the true output so that resetting the register presents -1 to the multiplier array, the change in algorithm between the sign bit and the rest of the bits is automatically taken care of.

The $D/2$ factor in the equations is used to round off the quotient. A double length dividend is assumed. The comparator is wired for a 2's complement comparison with the sign digit of the product and dividend crossed over, the dividend sign bit forming part of the multiplier word and the product sign bit forming part of the dividend word.

APPENDIX A

CONNECTION DIAGRAMS

Within this Appendix, the symbol shown at left below is used to represent the Am25S05, Am2505, or Am25L05. The symbol at left should be interpreted as equivalent to the symbol at right.

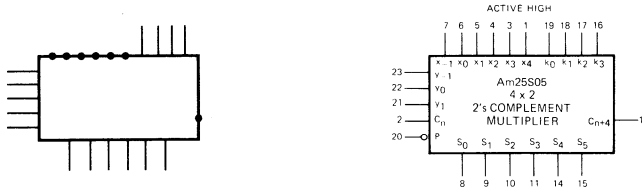


Table A-1 is a summary of the typical switching characteristics for each path through the multiplier. Table A-2 is a summary of speed and power for various size multiplier arrays using the parallelogram connection with carries interchanged (Reference Fig. A-1 and A-2).

TABLE A-1

TYPICAL SWITCHING CHARACTERISTICS

$$\left(\frac{t_{PHL} + t_{PLH}}{2} \right)$$

PATH	Am25S05	Am2505	Am25L05	UNIT
C _n to C _{n+4}	8.5	13.5	32.5	ns
C _n to S ₀₃	11.0	16.5	36.0	ns
C _n to S ₄₅	14.0	19.5	44.0	ns
k to C _{n+4}	8.25	13.5	31.0	ns
k to S ₀₃	11.5	16.5	36.5	ns
k to S ₄₅	14.0	21.5	51.5	ns
X to C _{n+4}	17.5	21.0	63.5	ns
X to S ₀₃	21.0	25.0	70.0	ns
X to S ₄₅	22.5	29.5	85.0	ns
Y to C _{n+4}	21.5	33.0	75.0	ns
Y to S ₀₃	23.0	35.0	83.5	ns
Y to S ₄₅	25.0	38.5	93.5	ns

TABLE A-2

**TYPICAL SPEED & POWER
FOR
TWO'S COMPLEMENT MULTIPLICATION**

ARRAY SIZE		Am25S05		Am2505		Am25L05	
Y • X	# DEVICES	SPEED ns	POWER WATTS	SPEED ns	POWER WATTS	SPEED ns	POWER WATTS
4x4	2	39	1.2	60	0.9	145	0.3
4x8	4	55	2.4	83	1.8	186	0.6
4x12	8	64	4.8	96	3.6	219	1.2
8x8	8	76	4.8	115	3.6	262	1.2
8x12	12	94	7.2	143	5.4	320	1.8
8x16	16	102	9.6	156	7.2	353	2.4
12x12	18	115	10.8	175	8.1	396	2.7
12x16	24	132	14.4	203	10.8	454	3.6
12x20	30	141	18.0	216	13.5	487	4.5
16x16	32	153	19.2	235	14.4	530	4.8
16x20	40	171	24.0	263	18.0	588	6.0
16x24	48	179	28.0	276	21.6	621	7.2
20x20	50	192	30.0	295	22.5	664	7.5
20x24	60	209	36.0	323	27.0	722	9.0
20x28	70	218	42.0	336	31.5	755	10.5
24x24	72	230	43.2	355	32.4	798	10.8
24x28	84	248	48.0	383	36.0	856	12.0
24x32	96	256	52.8	396	39.6	889	13.2
28x28	98	269	54.0	415	40.5	932	13.5
28x32	112	286	62.4	443	46.8	990	15.6
32x32	128	307	72.0	475	54.0	1066	18.0

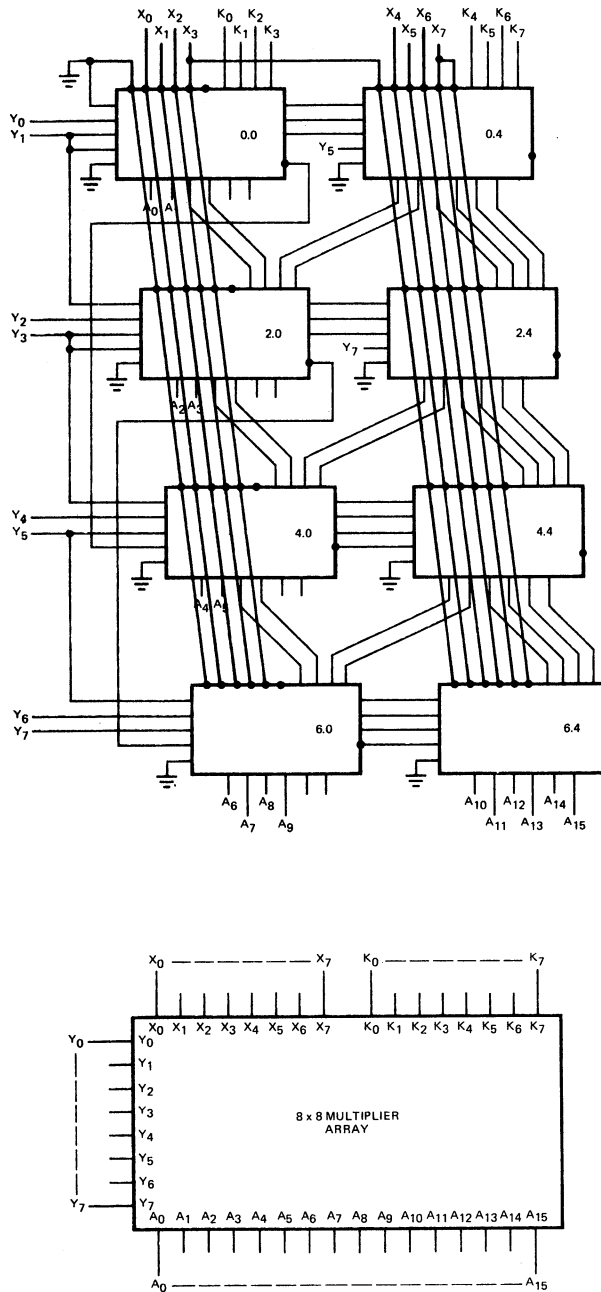


Figure A-1. 8 x 8 Multiplication Array for 2's Complement Numbers. Both the Actual Connection Diagram and System Block Diagram are Shown.

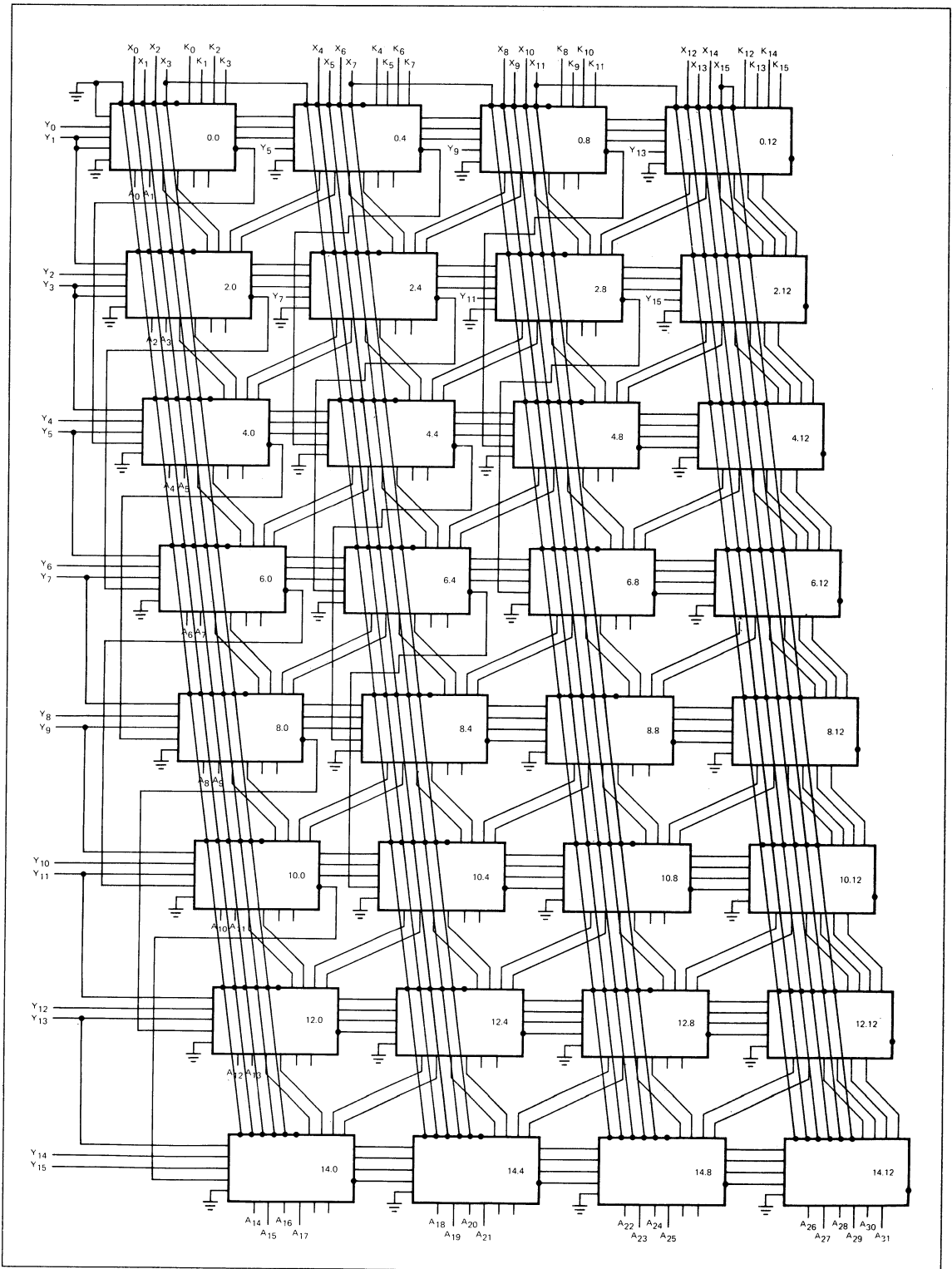


Figure A-2. 16 x 16 2's Complement Multiplication Array.

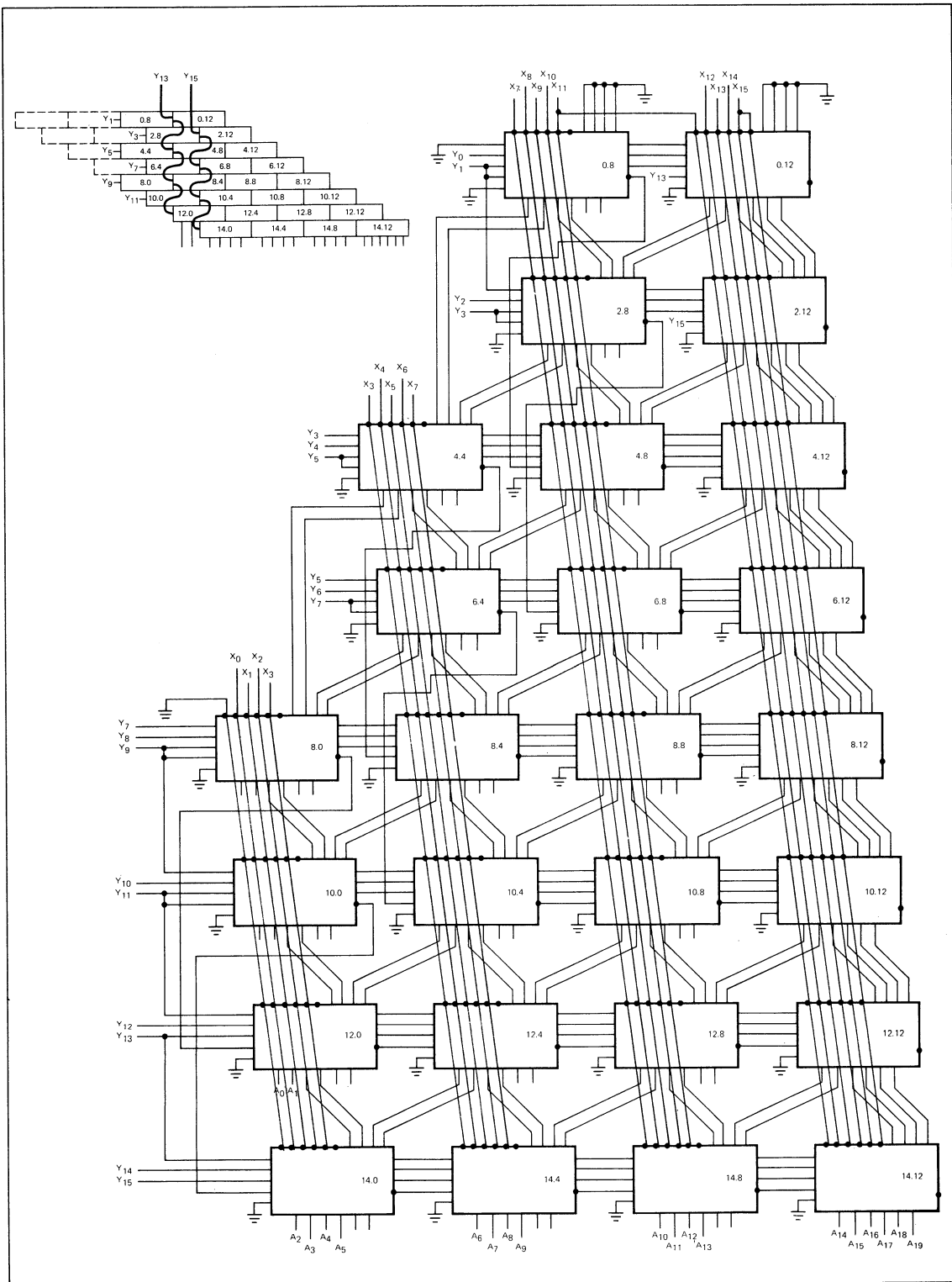


Figure A-3. 16 x 16 2's Complement Multiplication Array Truncated to a 20-bit Product with ~ 1LSB Accuracy.

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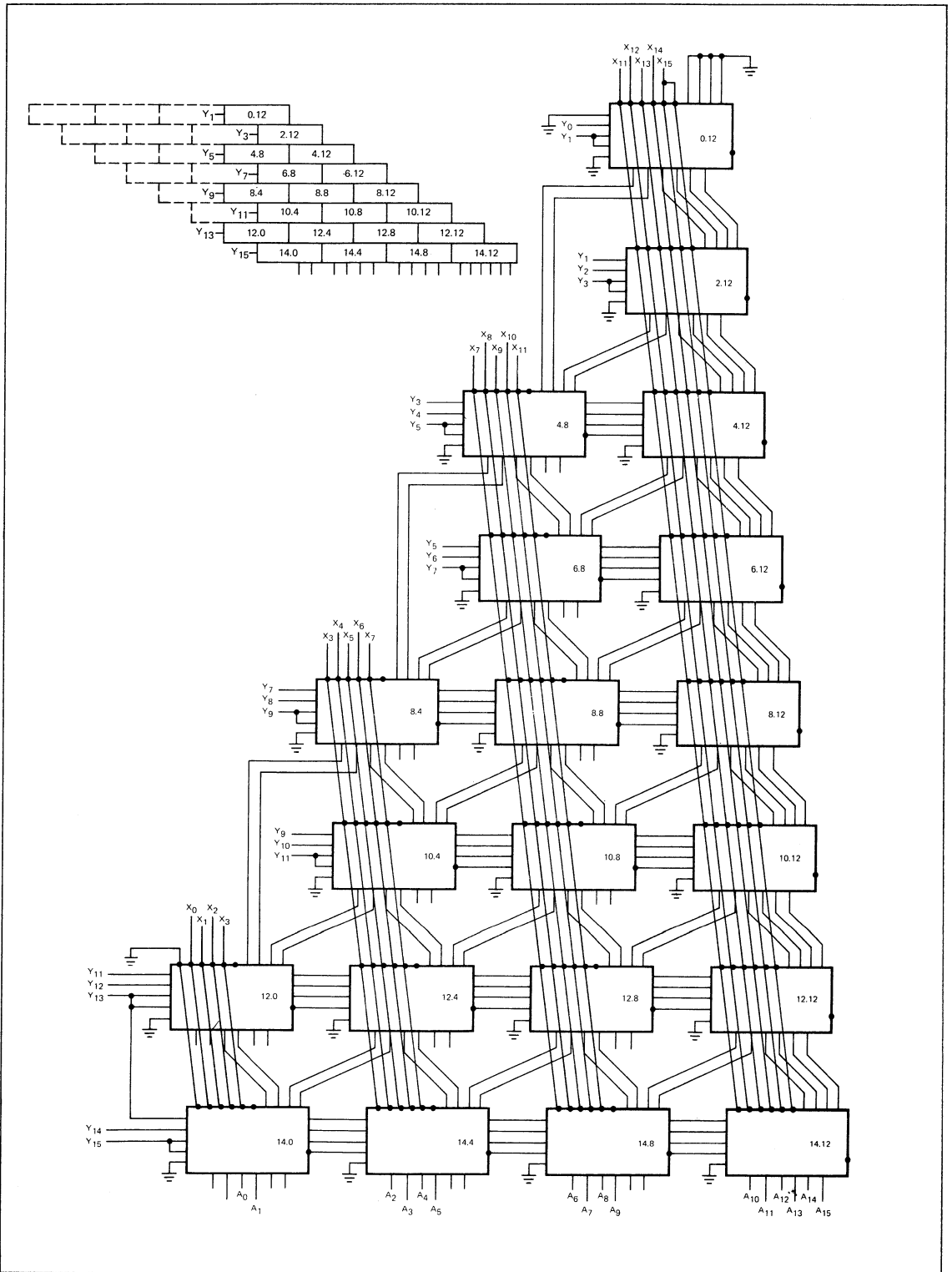
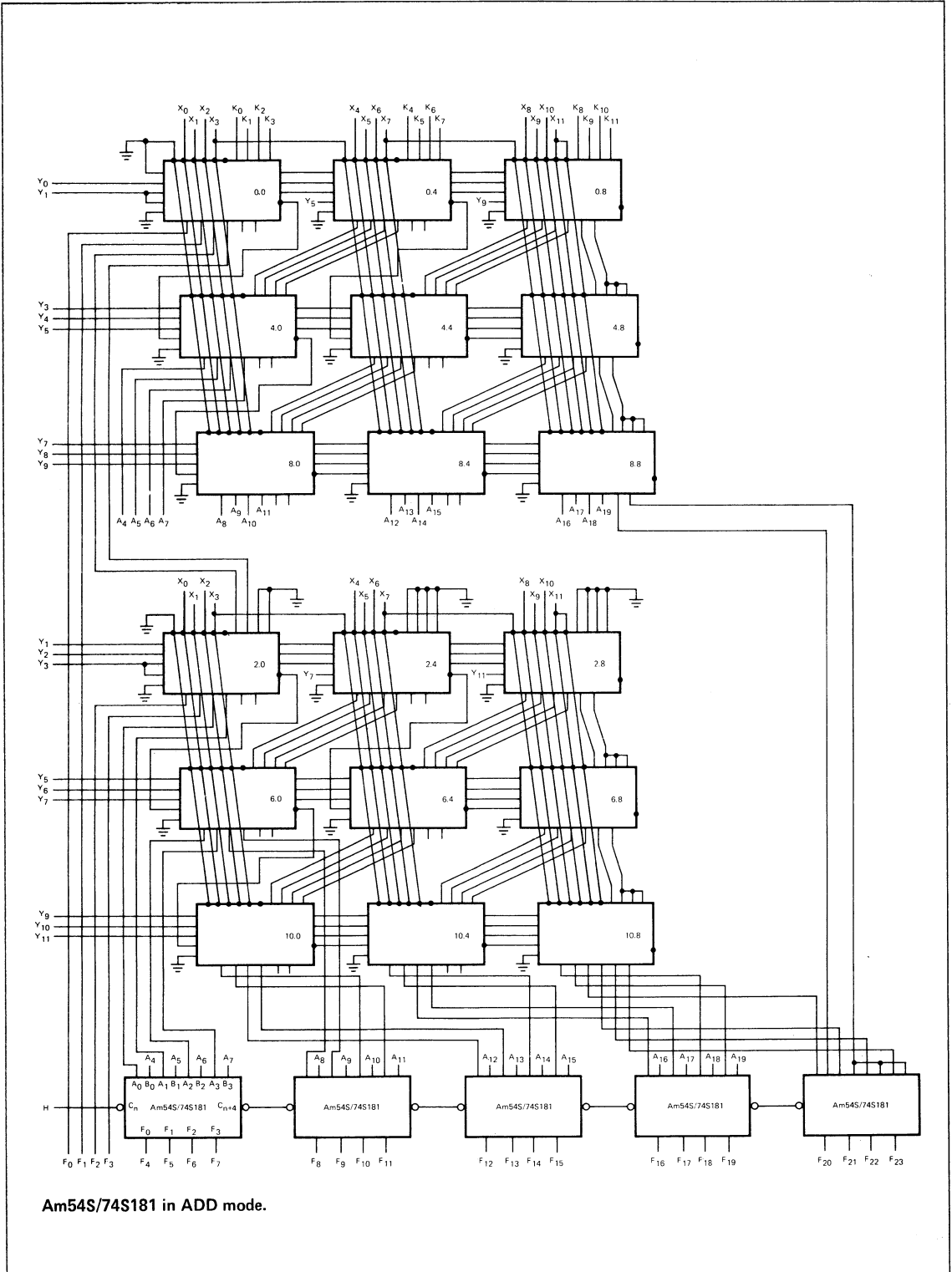


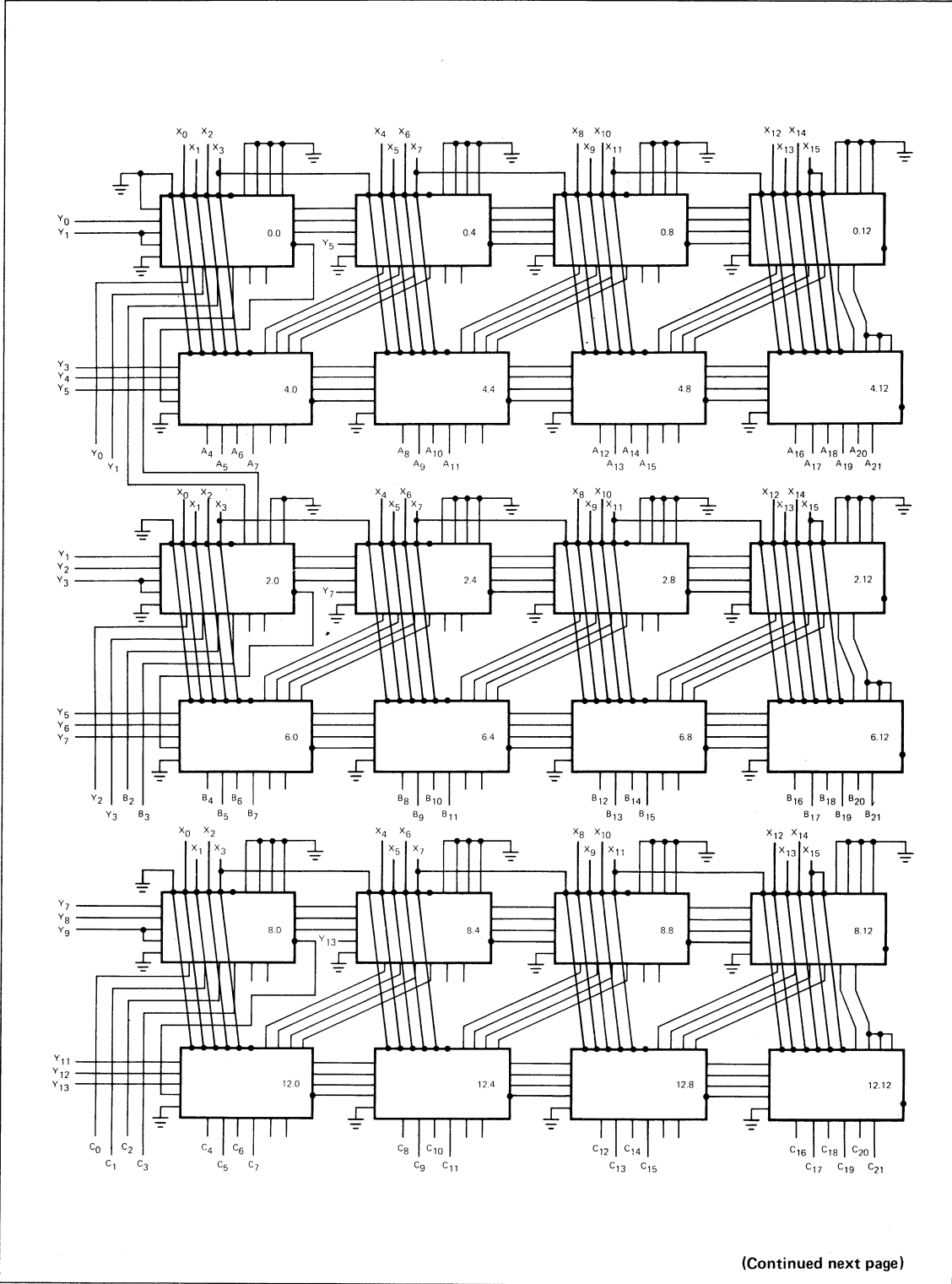
Figure A-4. 16 x 16 2's Complement Multiplication Array Truncated to a 16-bit Product with $\sim 1/2$ LSB Accuracy.



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Am54S/74S181 in ADD mode.

Figure A-5. 12 x 12 Multiplication Array Using one Level of Adders. (Similar to Figure 16 on 12 x 12 Array.)



(Continued next page)

Figure A-6. 16 x 16 Multiplier Using Two Levels of Adders, (Reference Fig. 17).

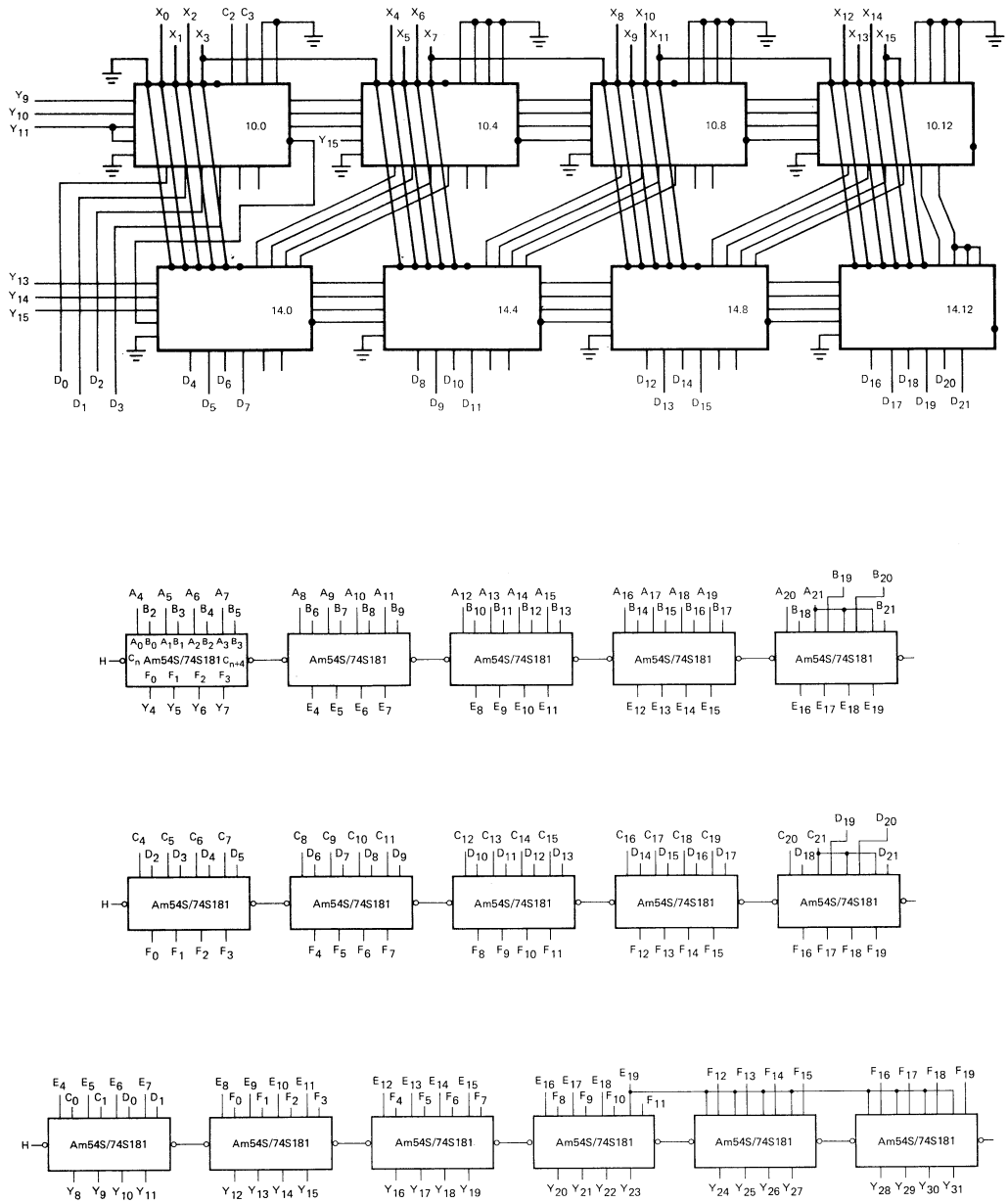


Figure A-6. (Con't) 16 x 16 Multiplier Using Two Levels of Adders, (Reference Fig. 17).

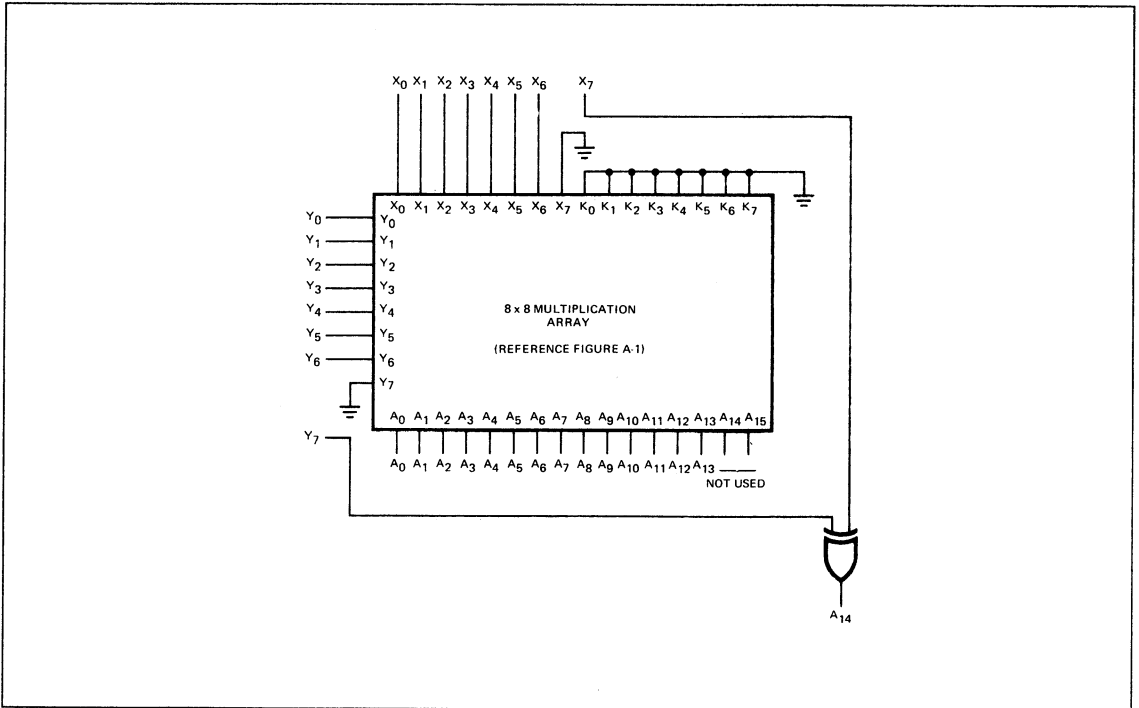


Figure A-7. 8 x 8 Multiplication Array for Sign-magnitude Numbers.

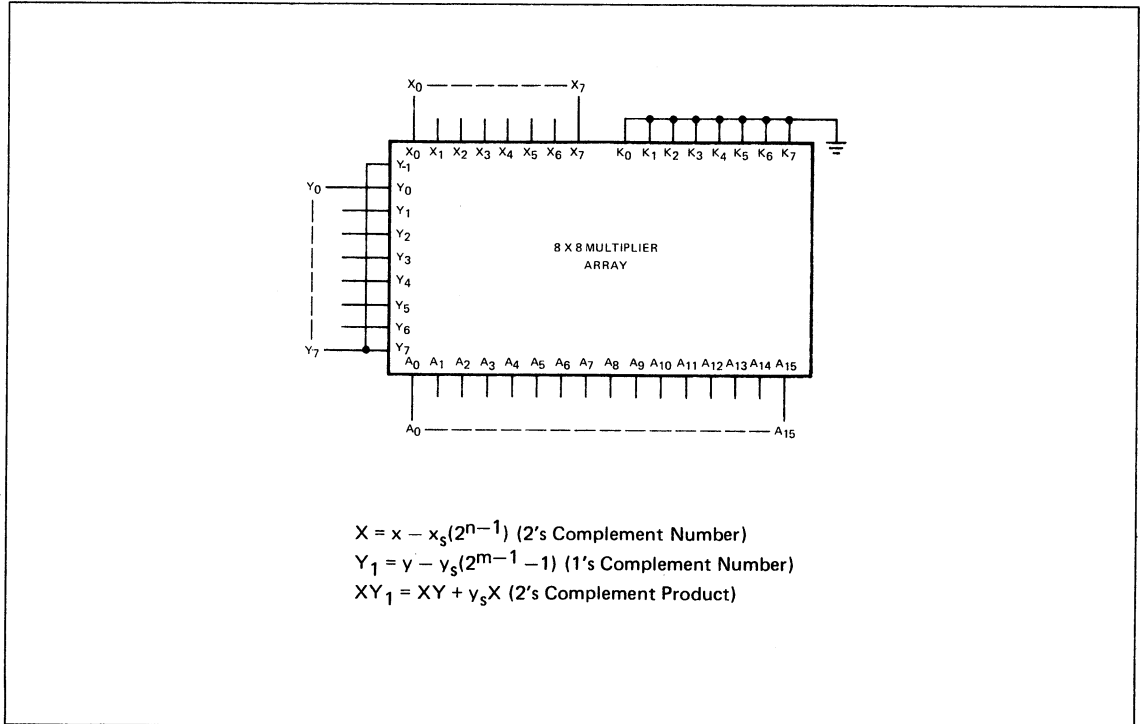
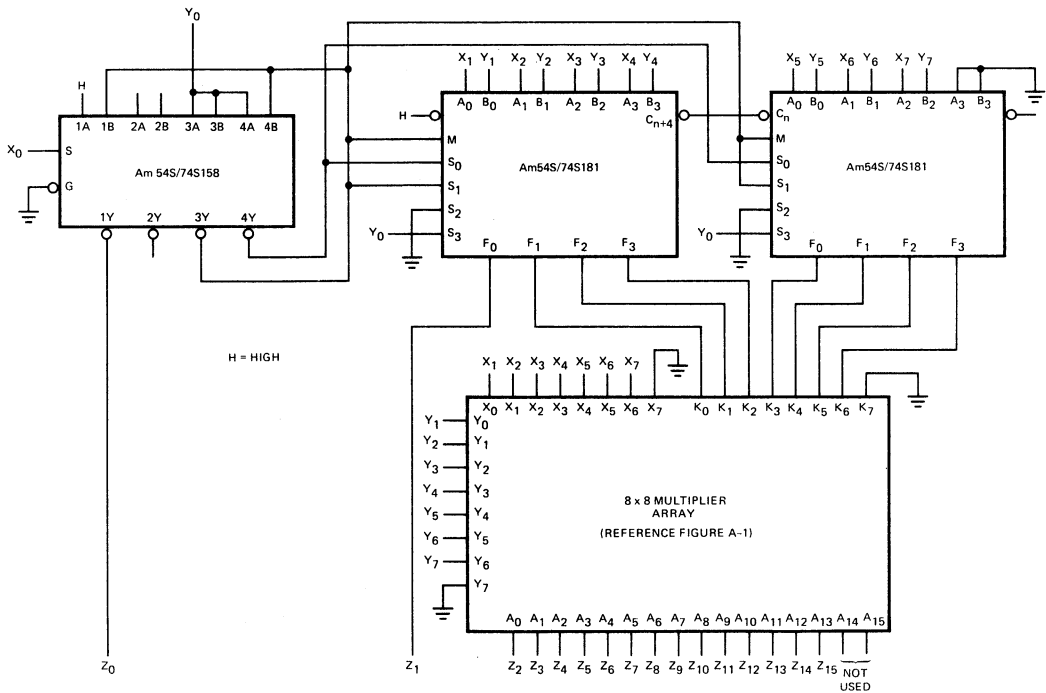


Figure A-8. 2's Complement Multiplicand, 1's Complement Multiplier and 2's Complement Product.

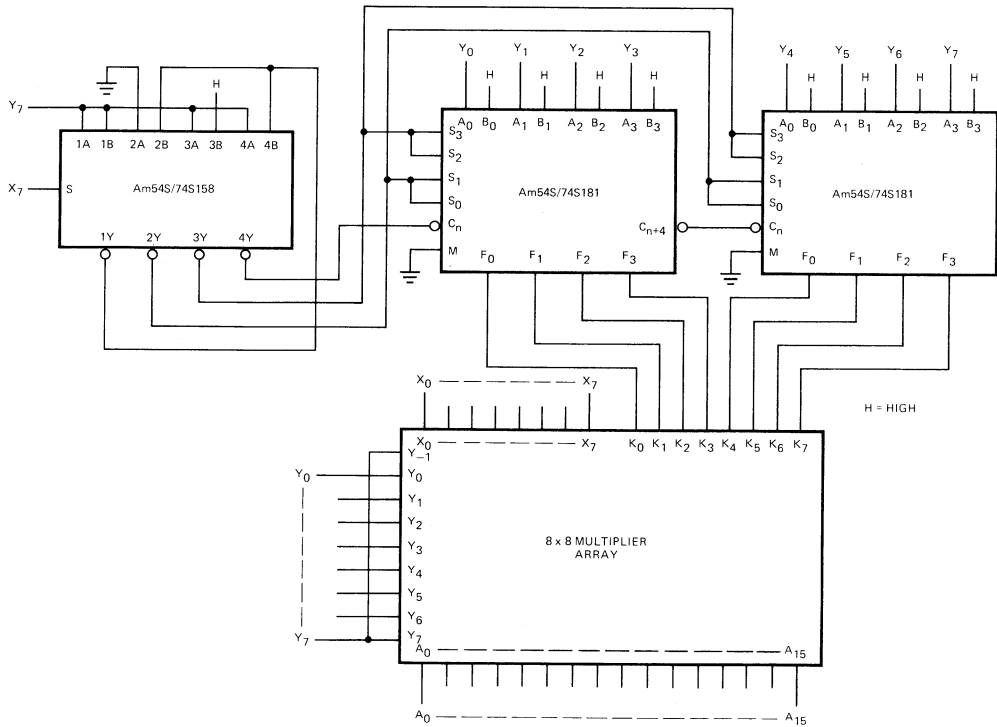


FUNCTION TABLE FOR DECODE

Y ₀	X ₀	C _n	M	S ₃	S ₂	S ₁	S ₀	S181 Function	Algorithm Function
0	0	X	H	L	L	H	H	0	Add 0
0	1	X	H	H	L	H	L	B	Add Y to XY
1	0	H	L	L	L	L	L	A	Add X to XY
1	1	H	L	H	L	L	H	A Plus B	Add X Plus Y to XY

0 = Logic "0" = L = LOW
 1 = Logic "1" = H = HIGH
 X = Don't Care

Figure A-9. 8 x 8 Multiplier for Unsigned Numbers Using the Product $X_e Y_e = 4xy + 2xy_0 + 2y_0x_0 + x_0y_0$.



FUNCTION TABLE

X_s	Y_s	Function	M	S_3	S_2	S_1	S_0	C_n
0	0	0	L	L	L	H	H	L
0	1	$Y-1$	L	H	H	H	H	H
1	0	-1	L	L	L	H	H	H
1	1	$Y+1$	L	L	L	L	L	L

Figure A-10. Multiplication of Two 8-bit 1's Complement Numbers Resulting in a 16-bit 1's Complement Product.

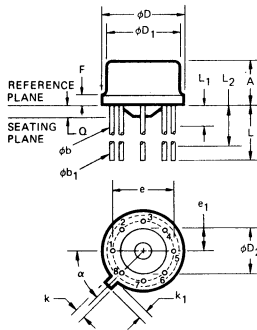
General Information

● Package Outlines	6–2
● Ordering Information	6–10
● Product Assurance Document 15-010 Rev. D	6–12
Sales Office Listing	6–18

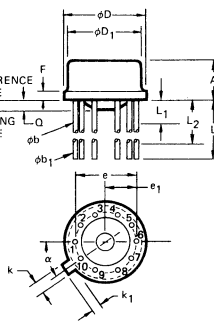
PACKAGE OUTLINES

METAL CAN PACKAGES

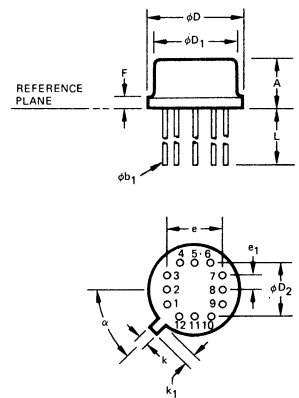
H-8-1



H-10-1



G-12-1



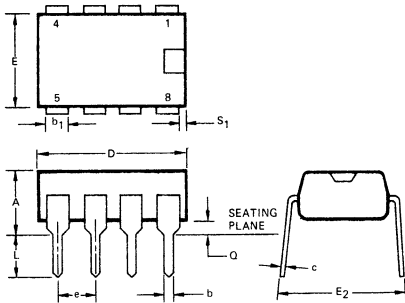
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Common Name	TO-99 Metal Can		TO-100 Metal Can		TO-8 Metal Can	
38510 Appendix C	A-1		A-2		-	
Parameters	Min.	Max.	Min.	Max.	Min.	Max.
A	.165	.185	.165	.185	.155	.180
e	.185	.215	.215	.245	.390	.410
e ₁	.090	.110	.105	.125	.090	.110
F	.013	.033	.013	.033	.020	.030
k	.027	.034	.027	.034	.024	.034
k ₁	.027	.045	.027	.045	.024	.038
L	.500	.570	.500	.610	.500	.600
L ₁		.050		.050		
L ₂	.250		.250			
α	45° BSC		36° BSC		45°	
ϕb	.016	.019	.016	.019		
ϕb_1	.016	.021	.016	.021	.016	.021
ϕD	.350	.370	.350	.370	.590	.610
ϕD_1	.305	.335	.305	.335	.540	.560
ϕD_2	.120	.160	.120	.160	.390	.410
Q	.015	.045	.015	.045		

Notes: 1. Standard lead finish is bright acid tin plate or gold plate.
 2. ϕb applies between L_1 and L_2 . ϕb_1 applies between L_1 and 0.500" beyond reference plane.

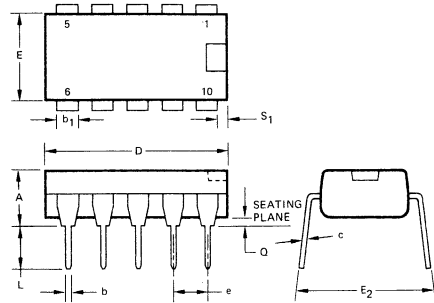
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MOLDED DUAL IN-LINE PACKAGES

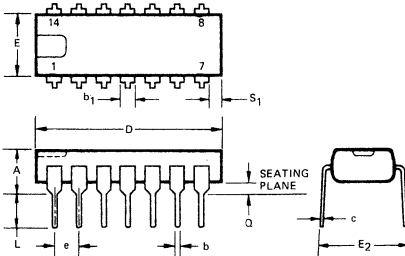
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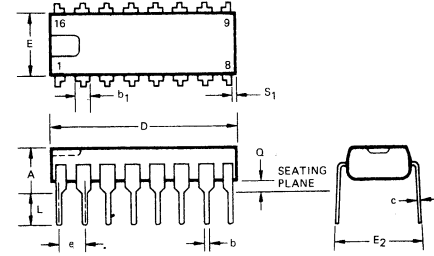
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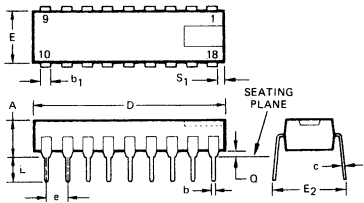
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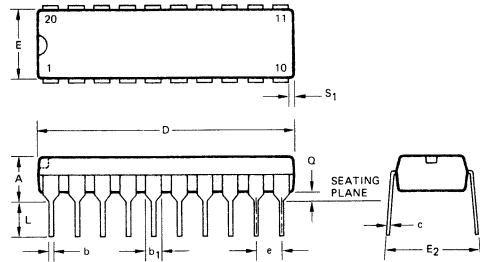
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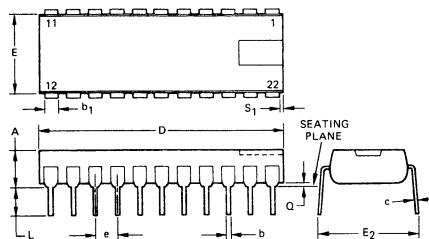
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P-20-1



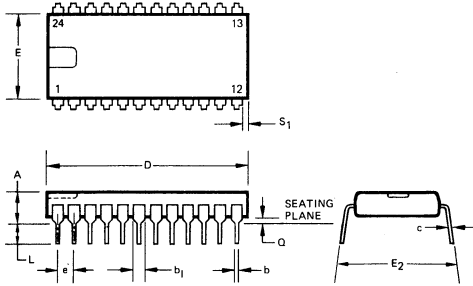
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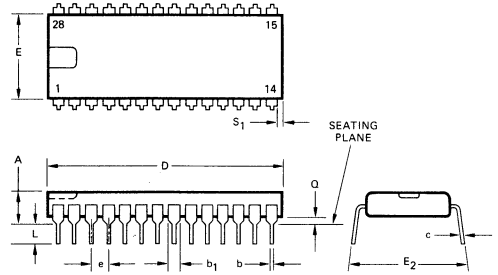
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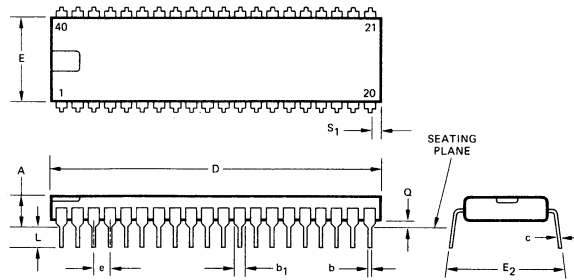
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P-40-1



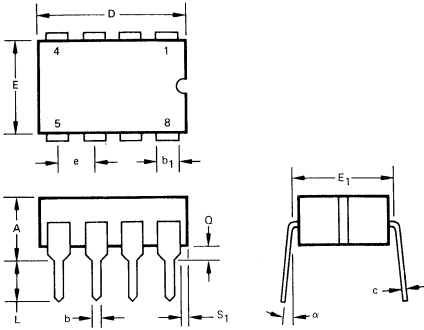
AMD Pkg.	P-8-1		P-10-1		P-14-1		P-16-1		P-18-1		P-20-1		P-22-1		P-24-1		P-28-1		P-40-1	
Parameters	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.
A	.150	.200	.150	.200	.150	.200	.150	.200	.150	.200	.150	.200	.150	.200	.170	.215	.150	.200	.150	.200
b	.015	.022	.015	.020	.015	.020	.015	.020	.015	.020	.015	.020	.015	.020	.015	.020	.015	.020	.015	.020
b ₁	.055	.065	.055	.065	.055	.065	.055	.065	.055	.065	.055	.065	.055	.065	.055	.065	.055	.065	.055	.065
c	.009	.011	.009	.011	.009	.011	.009	.011	.009	.011	.009	.011	.009	.011	.009	.011	.009	.011	.009	.011
D	.375	.395	.505	.550	.745	.775	.745	.775	.895	.925	1.010	1.050	1.080	1.120	1.240	1.270	1.450	1.480	2.050	2.080
E	.240	.260	.240	.260	.240	.260	.240	.260	.240	.260	.250	.290	.330	.370	.515	.540	.530	.550	.530	.550
E ₂	.310	.385	.310	.385	.310	.385	.310	.385	.310	.385	.310	.385	.410	.480	.585	.700	.585	.700	.585	.700
e	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110
L	.125	.150	.125	.150	.125	.150	.125	.150	.125	.150	.125	.150	.125	.160	.125	.160	.125	.160	.125	.160
Q	.015	.060	.015	.060	.015	.060	.015	.060	.015	.060	.015	.060	.015	.060	.015	.060	.015	.060	.015	.060
S ₁	.010	.030	.040	.070	.040	.065	.010	.040	.030	.040	.025	.055	.015	.045	.035	.065	.040	.070	.040	.070

Notes: 1. Standard lead finish is tin plate or solder dip.
 2. Dimension E₂ is an outside measurement.

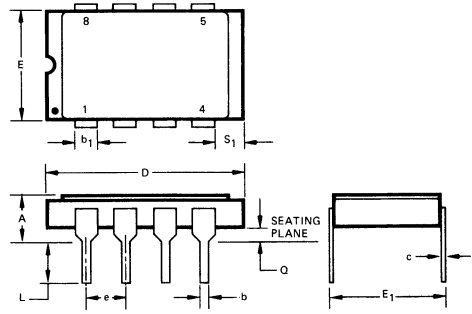
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HERMETIC DUAL IN-LINE PACKAGES

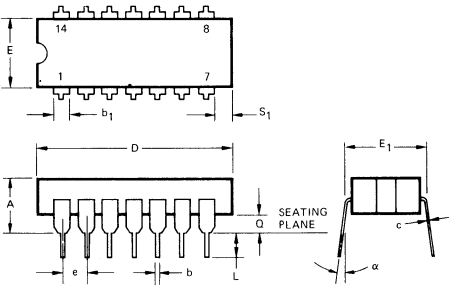
D-8-1



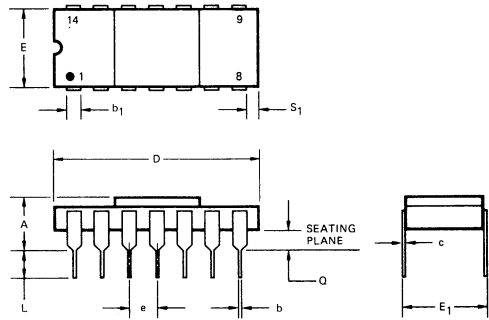
D-8-2



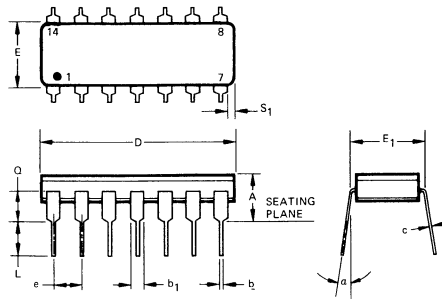
D-14-1



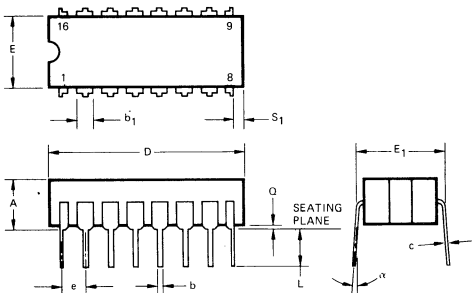
D-14-2



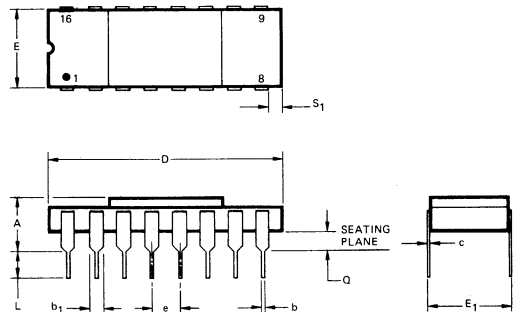
D-14-3



D-16-1



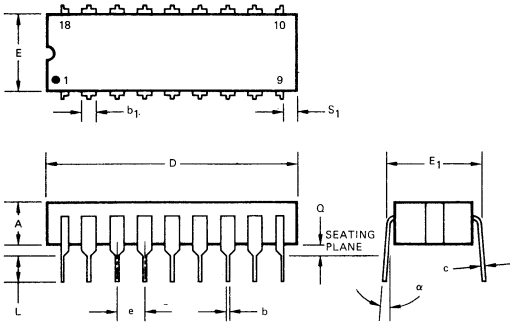
D-16-2



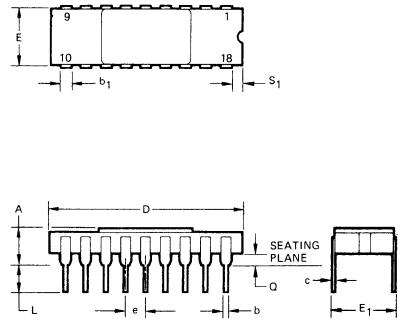
PACKAGE OUTLINES (Cont.)

HERMETIC DUAL IN-LINE PACKAGES (Cont.)

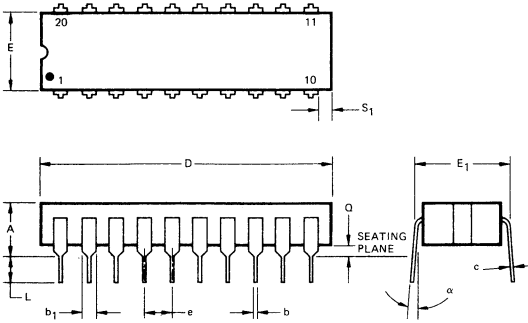
D-18-1



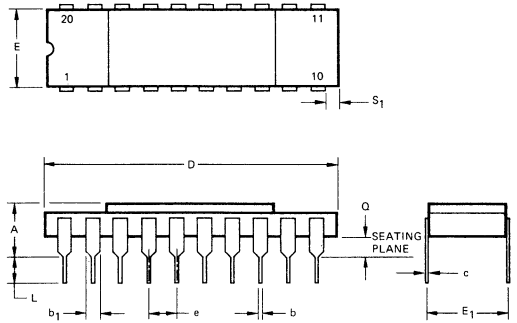
D-18-2



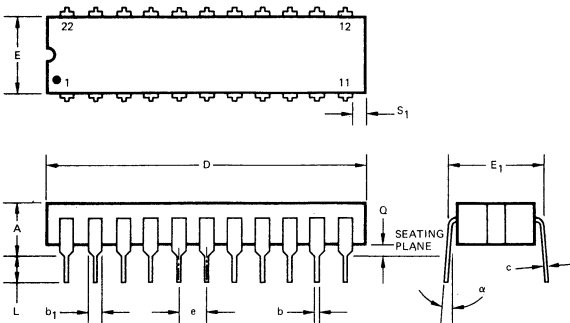
D-20-1



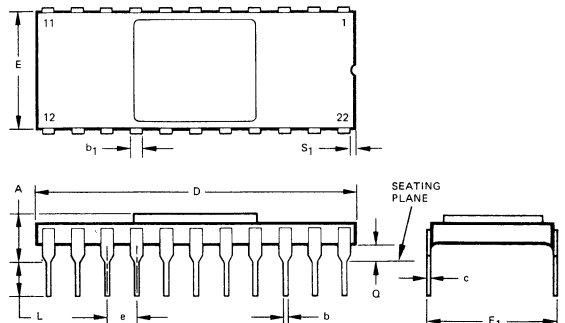
D-20-2



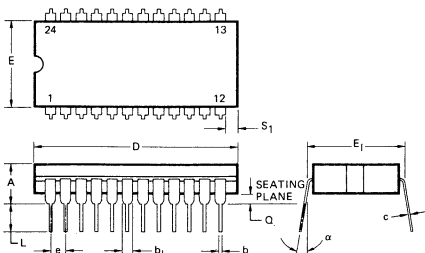
D-22-1



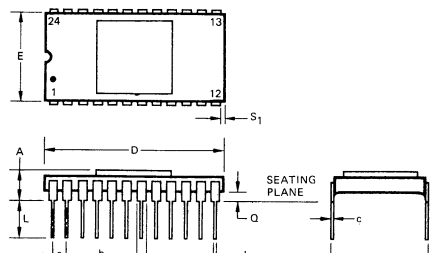
D-22-2



D-24-1 and D-24-4



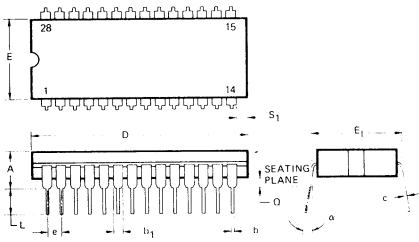
D-24-2



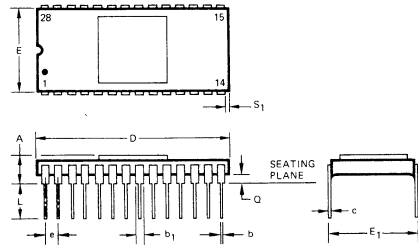
PACKAGE OUTLINES (Cont.)

HERMETIC DUAL IN-LINE PACKAGES (Cont.)

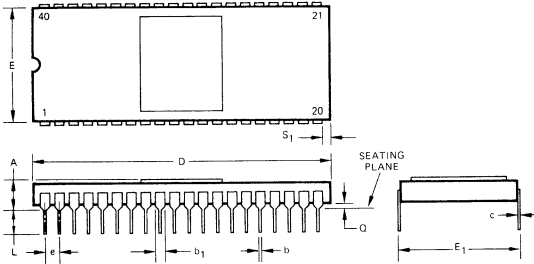
D-28-1



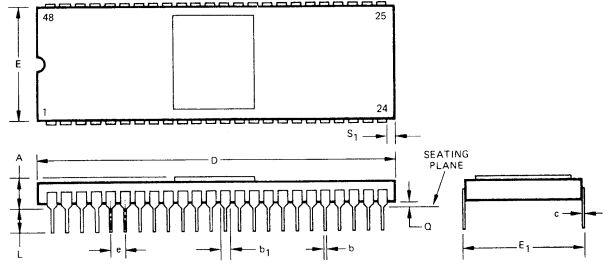
D-28-2



D-40-2



D-48-2



AMD Pkg.	D-8-1		D-8-2		D-14-1		D-14-2		D-14-3		D-16-1		D-16-2		D-18-1		D-18-2		D-20-1	
Common Name	CERDIP		SIDE-BRAZED		CERDIP		SIDE-BRAZED		METAL DIP		CERDIP		SIDE-BRAZED		CERDIP		SIDE-BRAZED		CERDIP	
38510 Appendix C	-		-		D-1(1)		D-1(3)		D-1(1)		D-2(1)		D-2(3)		-		-		-	
Parameters	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.
A	.130	.200	.100	.200	.130	.200	.100	.200	.100	.200	.130	.200	.100	.200	.130	.200	.100	.200	.140	.220
b	.016	.020	.015	.022	.016	.020	.015	.022	.015	.023	.016	.020	.015	.022	.016	.020	.015	.022	.016	.020
b ₁	.050	.070	.040	.065	.050	.070	.040	.065	.030	.070	.050	.070	.040	.065	.050	.070	.040	.065	.050	.070
c	.009	.011	.008	.013	.009	.011	.008	.013	.008	.011	.009	.011	.008	.013	.009	.011	.008	.013	.009	.011
D	.370	.400	.500	.540	.745	.785	.690	.730	.660	.785	.745	.785	.820	.870	.920	.850	.930	.935	.970	
E	.240	.285	.260	.310	.240	.285	.260	.310	.230	.265	.240	.310	.260	.310	.280	.310	.260	.310	.245	.285
E ₁	.300	.320	.290	.320	.290	.320	.290	.320	.290	.310	.290	.320	.290	.320	.290	.320	.290	.320	.290	.320
e	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110
L	.125	.150	.125	.160	.125	.160	.125	.160	.100	.150	.125	.150	.125	.160	.125	.150	.125	.160	.125	.150
Q	.015	.060	.020	.060	.015	.060	.020	.060	.020	.080	.015	.060	.020	.060	.015	.060	.020	.060	.015	.060
S ₁	.004		.005		.010		.005		.020		.005		.005		.005		.005		.005	
α	3°	13°			3°	13°			3°	13°			3°	13°			3°	13°		
Standard Lead Finish	b		b or c		b		b or c		c		b		b or c		b		b or c		b	

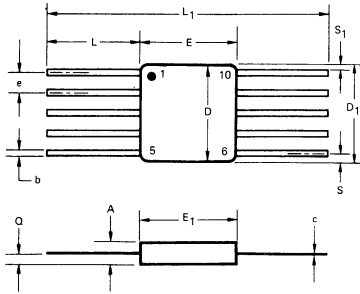
AMD Pkg.	D-20-2		D-22-1		D-22-2		D-24-1		D-24-2		D-24-4		D-28-1		D-28-2		D-40-2		D-48-2	
Common Name	SIDE-BRAZED		CERDIP		SIDE-BRAZED		CERDIP		SIDE-BRAZED		CERVIEW		CERDIP		SIDE-BRAZED		SIDE-BRAZED		SIDE-BRAZED	
38510 Appendix C	-		-		-		D-3(1)		D-3(3)		-		-		-		-		-	
Parameters	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.
A	.100	.200	.140	.220	.100	.200	.150	.225	.100	.200	.150	.225	.150	.225	.100	.200	.100	.200	.100	.200
b	.015	.022	.016	.020	.015	.022	.016	.020	.015	.022	.016	.020	.016	.020	.015	.022	.015	.022	.015	.022
b ₁	.040	.065	.045	.065	.030	.060	.045	.065	.030	.060	.045	.065	.045	.065	.030	.060	.030	.060	.030	.060
c	.008	.013	.009	.011	.008	.013	.009	.011	.008	.013	.009	.011	.009	.012	.008	.013	.008	.013	.008	.013
D	.950	1.010	1.045	1.110	1.050	1.110	1.230	1.285	1.170	1.200	1.235	1.280	1.440	1.490	1.380	1.420	1.960	2.040	2.370	2.430
E	.260	.310	.360	.405	.360	.410	.510	.545	.550	.610	.510	.550	.510	.545	.560	.600	.550	.610	.570	.610
E ₁	.290	.320	.390	.420	.390	.420	.600	.620	.590	.620	.600	.630	.600	.620	.590	.620	.590	.620	.590	.620
e	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110	.090	.110
L	.125	.160	.125	.160	.125	.160	.120	.160	.120	.160	.120	.160	.125	.160	.120	.160	.120	.160	.125	.160
Q	.020	.060	.015	.060	.020	.060	.015	.060	.020	.060	.015	.060	.015	.060	.020	.060	.020	.060	.020	.060
S ₁	.005		.005		.005		.010		.005		.010		.010		.005		.005		.005	
α			3°	13°			3°	13°			3°	13°	3°	13°			3°	13°		
Standard Lead Finish	b or c		b		b or c		b		b or c		b		b		b		b or c		b or c	

- Notes: 1. Load finish b is tin plate. Finish c is gold plate.
 2. Used only for LM108/LM108A.
 3. Dimensions E and D allow for off-center lid, meniscus and glass overrun.

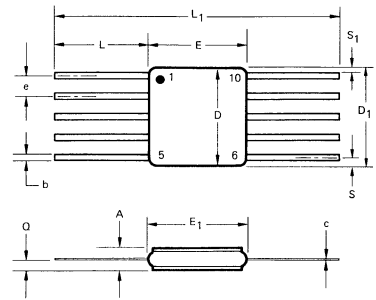
PACKAGE OUTLINES (Cont.)

FLAT PACKAGES

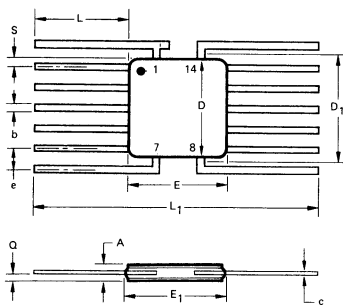
F-10-1



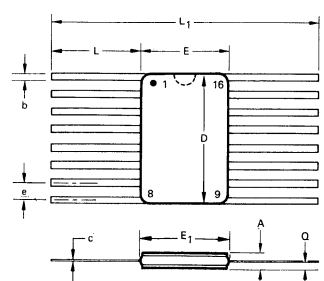
F-10-2



F-14-1 and F-14-2

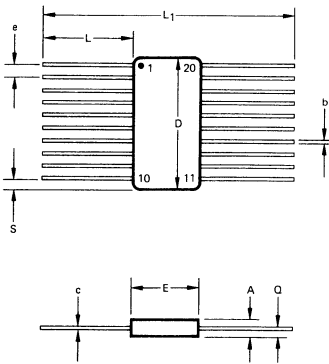


F-16-1 and F-16-2

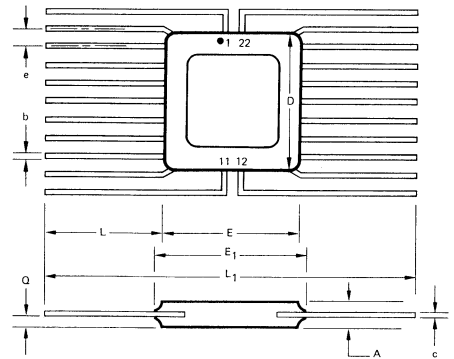


Note: Notch is pin 1 index on cerpack.

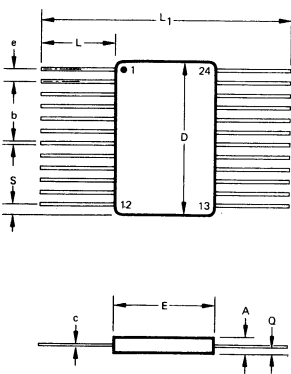
F-20-1



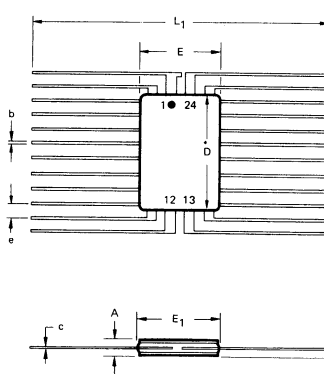
F-22-1



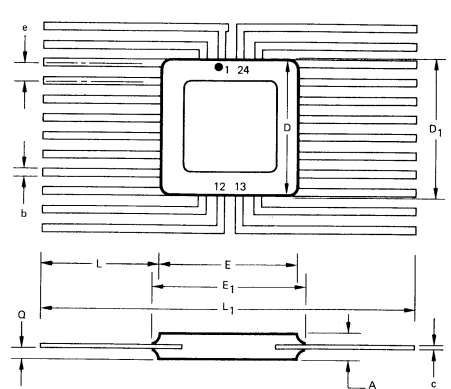
F-24-1



F-24-2



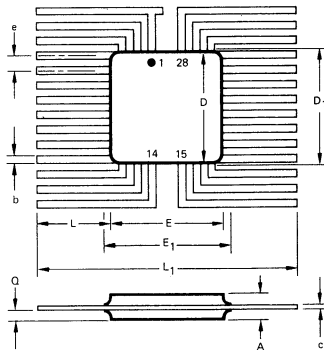
F-24-3



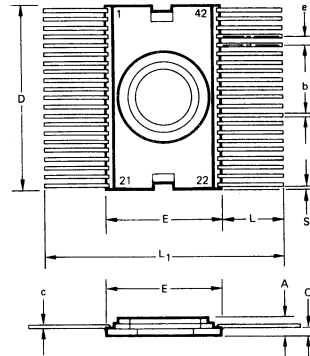
PACKAGE OUTLINES (Cont.)

FLAT PACKAGES (Cont.)

F-28-1



F-42-1



AMD Pkg.	F-10-1		F-10-2		F-14-1		F-14-2		F-16-1		F-16-2		F-20-1		F-22-1	
Common NAME	CERPACK		METAL FLAT PAK		CERPACK		METAL FLAT PAK		CERPACK		METAL FLAT PAK		CERPACK		METAL FLAT PAK	
38510 Appendix C	F-4		F-4		F-1		F-1		F-5		-		-		-	
Parameters	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.
A	.045	.080	.045	.080	.045	.080	.045	.085	.045	.085	.045	.085	.045	.085	.045	.090
b	.015	.019	.012	.019	.015	.019	.012	.019	.015	.019	.015	.019	.015	.019	.015	.019
c	.004	.006	.003	.006	.004	.006	.003	.006	.004	.006	.003	.006	.004	.006	.003	.006
D	.230	.255	.235	.275	.230	.255	.230	.270	.370	.425	.370	.400	.490	.520	.380	.420
D ₁				.275				.280				.410				.440
E	.240	.260	.240	.260	.240	.260	.240	.260	.245	.285	.245	.285	.245	.285	.380	.420
E ₁		.275		.280		.275		.280		.290		.305		.290		.440
e	.045	.055	.045	.055	.045	.055	.045	.055	.045	.055	.045	.055	.045	.055	.045	.055
L	.300	.370	.300	.370	.300	.370	.300	.370	.300	.370	.300	.370	.300	.370	.250	.320
L ₁	.920	.980	.920	.980	.920	.980	.920	.980	.920	.980	.920	.980	.920	.980	.920	.980
Q	.010	.040	.010	.040	.010	.040	.010	.040	.020	.040	.010	.040	.020	.040	.010	.040
S ₁	.005		.005		.005		.005		.005		.005		.005			
Standard Lead Finish	b		c		b		c		b		c		b		c	

AMD Pkg.	F-24-1		F-24-2		F-24-3		F-28-1		F-42-1	
Common Name	CERPACK		METAL FLAT PAK		METAL FLAT PAK		METAL FLAT PAK		CERAMIC FLAT PAK	
38510 Appendix C	F-6		F-8		-		-		-	
Parameters	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.
A	.050	.090	.045	.090	.045	.090	.045	.080	.070	.115
b	.015	.019	.015	.019	.015	.019	.015	.019	.017	.023
c	.004	.006	.003	.006	.003	.006	.003	.006	.006	.012
D	.580	.620	.360	.410	.380	.420	.360	.410	1.030	1.090
D ₁				.420		.440		.410		1.090
E	.360	.385	.245	.285	.380	.420	.360	.410	.620	.660
E ₁		.410		.305		.440		.410		.660
e	.045	.055	.045	.055	.045	.055	.045	.055	.045	.055
L	.265	.320	.300	.370	.250	.320	.270	.320	.320	.370
L ₁	.920	.980	.920	.980	.920	.980	.955	1.000	1.300	1.370
Q	.020	.040	.010	.040	.010	.040	.010	.040	.020	.060
S ₁	.005		.005		0		0		.005	
Standard Lead Finish	b		c		c		c		c	

Notes: 1. Lead finish b is tin plate. Finish c is gold plate.
 2. Dimensions E₁ and D₁ allow for off-center lid, meniscus, and glass overrun.

ORDERING INFORMATION

All Advanced Micro Devices' products listed are stocked locally and distributed nationally by Franchised Distributors. See back of this book for the location nearest you. Please consult them for the latest price revisions. For direct factory orders, call Advanced Micro Devices, 901 Thompson Place, Sunnyvale, California 94086, (408) 732-2400, TWX: 910-339-9280, TELEX: 34-6306.

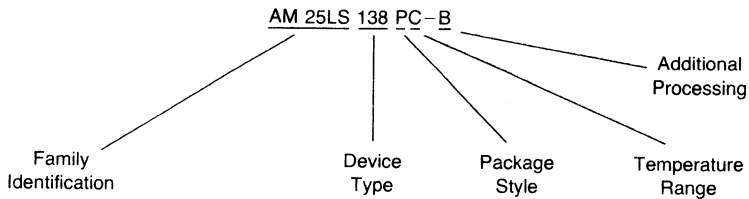
Minimum Order

The minimum direct factory order is \$100.00 for a standard product.

The minimum direct factory order for Class B, burned-in, product is \$250.00.

Proprietary Product Ordering, Package and Temperature Range Codes

The following scheme is used to identify Advanced Micro Devices' proprietary products.



Package Style

D = Hermetic DIP
 F = Flat Package
 P = Molded DIP
 X = Dice

Temperature Range

C = Commercial
 0°C to +70°C
 M = Military
 -55°C to +125°C

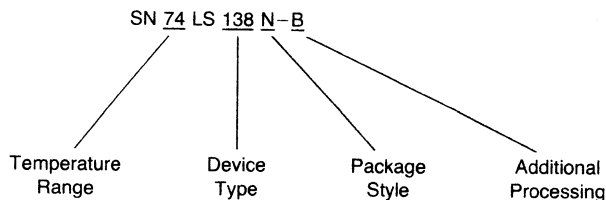
Additional Processing

B = Burn-in (Signifies full MIL-STD-883 Class B product for military temperature range devices)
 T = Additional high temperature testing

Second Source Product Ordering, Package and Temperature Range Codes

An order number and marking system identical to the original manufacturer's is used for the Advanced Micro Devices' pin-for-pin and electrically equivalent circuit.

The following example is the ordering scheme for Advanced Micro Devices' second source to Texas Instruments' products.



Package Style

J = Hermetic DIP
 N = Molded DIP
 W = Flat Package
 X = Dice

Temperature Range

74 = Commercial
 0°C to +70°C
 54 = Military
 -55°C to +125°C

Additional Processing

B = Burn-in (Signifies full MIL-STD-883 Class B product for military temperature range devices)
 T = Additional high temperature testing

STANDARD PRODUCT PROCESSING AND OPTIONS

1. AMD STANDARD PRODUCT – CLASS C PROCESSING

All products manufactured by Advanced Micro Devices, including Bipolar Logic and Interface, Memory and Microprocessors, Linear and MOS/LSI meet the quality requirements of MIL-M-38510. In addition all products, both commercial and military temperature range receive the 100% screening procedures defined in the current revision of MIL-STD-883, Method 5004, Class C. This processing is described in Advanced Micro Devices' Product Assurance Document 15-010.

- a) **Internal visual inspection:** Method 2010, Condition B.
- b) **High temperature storage:** Method 1008, Condition C; 150°C, 24 hours.
- c) **Temperature cycling:** Method 1010, Condition C; -65°C, 150°C, 10 cycles.
- d) **Constant acceleration:** Method 2001, Condition E; 30,000 g., Y₁ plane. (Hermetic packages only.)
- e) **Fine leak:** Method 1014, Condition A; 5×10^{-8} atm cc per second. (Hermetic packages only.)
- f) **Gross leak:** Method 1014, Condition C., Step 2. (Hermetic packages only.)
- g) **Continuity test** at 100°C to 0.01% AQL. (Molded packages only.)
- h) **Final electrical test:** 100% D.C. and functional testing at 25°C and Group A sample per Method 5005.

To order this product, use the order number shown for the product desired. Example: AM2501DM for full military temperature range part in dual-in-line package, AM2501DC for commercial temperature range in dual-in-line package.

As noted, all material is processed to Class C and no additional price adders are imposed to deliver this level of reliability.

2. CLASS B PROCESSING

Military Temperature Range

Standard product is upgraded to Class B with a 160-hour burn-in at 125°C followed by 100% electrical testing of D.C. parameters at 25°C, 125°C, -55°C and A.C. parameters at 25°C.

Burn-in conditions are steady state power (MIL-STD-883, Method 1015.1, Condition B) for linear circuits, and steady state power and reverse bias (Condition C) for all others. Standard burn-in circuit specifications for any device are available upon request. Condition D burn-in is available to special order. Consult your local AMD sales office for price and delivery.

To order this product, use the order number shown for the product desired and add the suffix "B". Example: AM2501DM-B for military temperature product in dual-in-line package with burn-in as described, SN54LS174W-B for military temperature range product in flat pack with burn-in. This processing meets all of the requirements of MIL-STD-883, Class B product.

Commercial Temperature Range

Standard AMD Class C commercial temperature range product is burned-in for use in non-military systems to a modified Class B program. A 160 hour burn-in, to a method meeting the requirements of Method 1015.1, Conditions A and B, is followed by the standard Class C electrical test procedures.

To order this level of screening, use the order number shown for the commercial device and add the suffix "B". Examples: AM25LS175DC-B and SN74LS153N-B.

3. CLASS S PROCESSING (FORMERLY CLASS A)

Class S processing is recommended only for applications where replacement is extremely difficult and reliability is imperative. This material is only produced to special order. Consult AMD for further details.

4. DICE

To assist hybrid manufacturers on prototype products, all AMD dice are available in quantities of 10 pieces or more. All dice are supplied in carriers, are glass scratch protected, and except for some LSI devices, are subjected to complete functional and parametric testing. Advanced Micro Devices' dice are 100% optically inspected to meet MIL-STD-883, Method 2010 Cond. B quality levels. Detailed information on additional extended dice testing and processing is available by contacting Advanced Micro Devices.

PRODUCT ASSURANCE

MIL-M-38510 • MIL-STD-883

AMD Document 15-010 Rev. D

The product assurance program at Advanced Micro Devices defines manufacturing flow, establishes standards and controls, and confirms the product quality at critical points. Standardization under this program assures that all products meet military and government agency specifications for reliable ground applications. Further screening for users desiring flight hardware and other higher reliability classes is simplified because starting product meets all initial requirements for high-reliability parts.

The quality standards and screening methods of this program are equally valuable for commercial parts where equipment must perform reliably with minimum field service.

Two military documents provide the foundation for this program. They are:

MIL-M-38510 – General Specification for Microcircuits
MIL-STD-883 – Test Methods and Procedures for Microelectronics

MIL-M-38510 describes design, processing and assembly workmanship guidelines for military and space-grade integrated circuits. All circuits manufactured by Advanced Micro Devices for full temperature range (-55°C to $+125^{\circ}\text{C}$) operation meet these quality requirements of MIL-M-38510.

MIL-STD-883 defines detail testing and inspection methods for integrated circuits. Three of the methods are quality and processing standards directly related to product assurance:

Test Method 2010 defines the visual inspection of integrated circuits before sealing. By confirming fabrication and assembly quality, inspection to this standard assures the user of reliable circuits in long-term field applications. Standard inspection at Advanced Micro Devices includes all the requirements of the latest revision of Method 2010, condition B.

Test Method 5004 defines three reliability classes of parts. All must receive certain basic inspection, preconditioning and screening stresses. The classes are:

Class C – Used where replacement can be readily accomplished. Screening steps are given in the AMD processing flow chart.

Class B – Used where maintenance is difficult or expensive and where reliability is vital. Devices are upgraded from Class C to Class B by 160-hour burn-in at 125°C followed by more extensive electrical measurements. All other screening requirements are the same.

Class A – Used where replacement is extremely difficult and reliability is imperative. Class A screening selects extra reliability parts by expanded visual and X-ray inspection, further burn-in, and tighter sampling inspection.

All hermetically sealed integrated circuits (military and commercial) manufactured by Advanced Micro Devices are screened to MIL-STD-883, Class C.

Optional extended processing to MIL-STD-883, Class B is available for all AMD integrated circuits. Parts procured to this screening are marked with a “-B” following the standard part number, except that linear 100, 200 or 300 series are marked “/883B”.

All molded integrated circuits receive Class C screening except that centrifuge and hermeticity steps are omitted for solid-package parts.

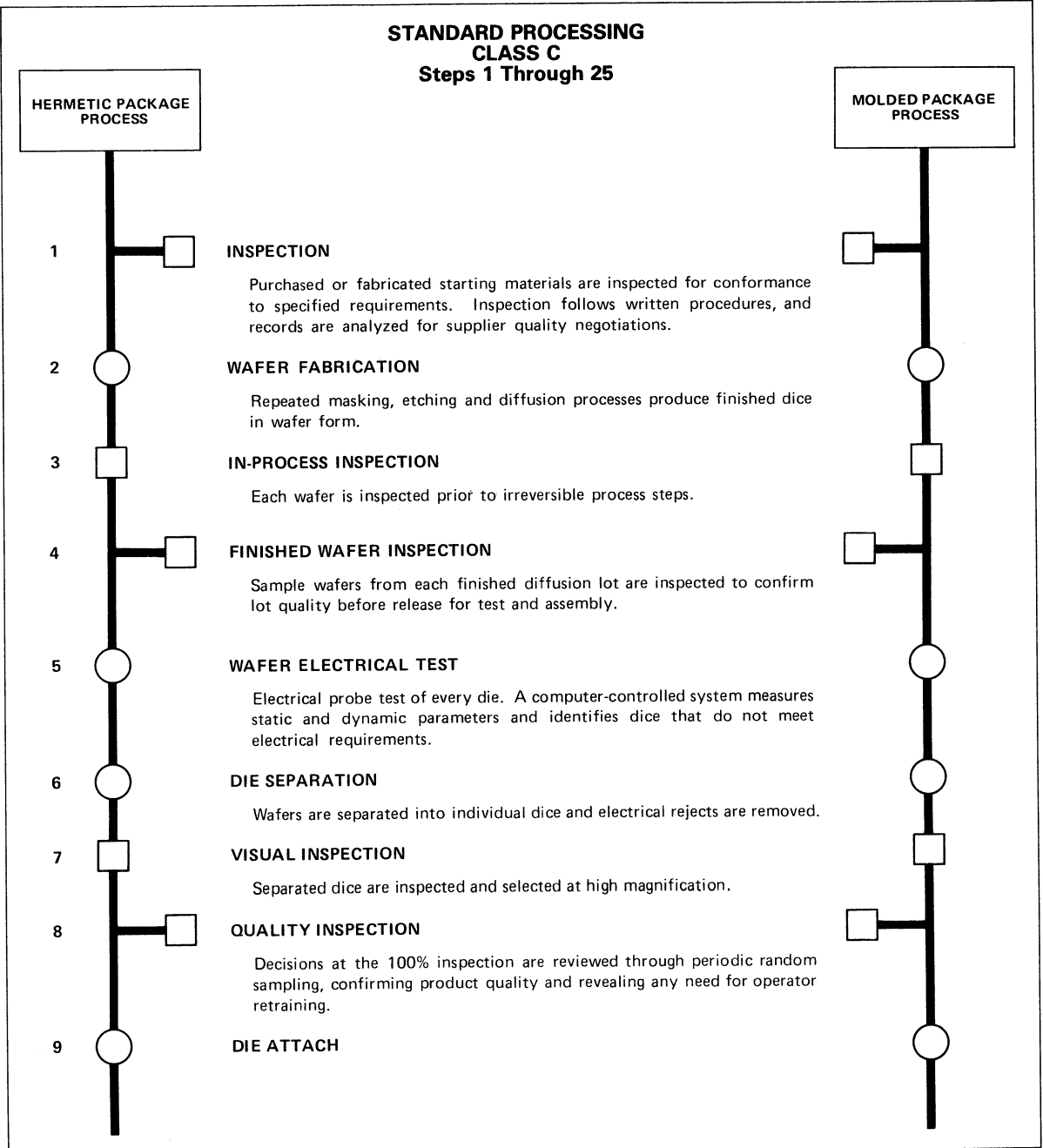
Test Method 5005 defines qualification and quality conformance procedures. Subgroups, tests and quality levels for each class are given for Group A (electrical), Group B (mechanical quality measurements related to the user’s assembly environment), Group C (die related tests) and Group D (package related tests). Group A tests are always performed; Group B, C and D may be specified by the user. Tables I, II, III and IV give standard test groupings and quality levels for Class B screened devices. These quality levels are used as a minimum for all tests for either Class B or Class C parts.

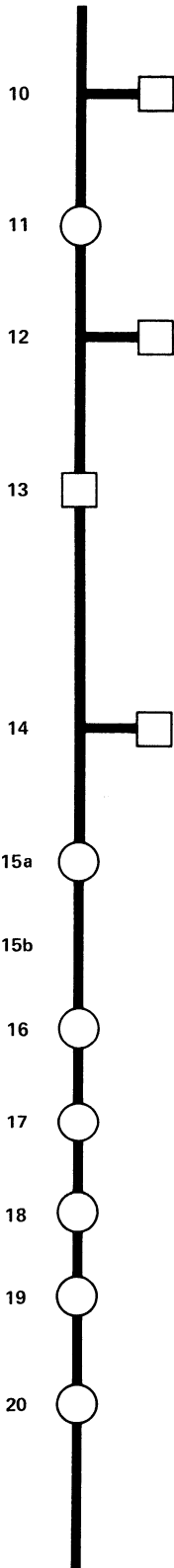
**MANUFACTURING, SCREENING AND INSPECTION
FOR
INTEGRATED CIRCUITS**

All integrated circuits are screened to MIL-STD-883, Method 5004, Class C; quality conformance inspection where required is performed to Class B quality levels on either Class B or Class C product.

All full-temperature-range (-55°C to +125°C) circuits are manufactured to the workmanship requirements of MIL-M-38510.

The flow chart identifies processing steps as they relate to MIL-STD-883 and MIL-M-38510.





QUALITY INSPECTION

Strength of die attachment, position of die and visual quality of eutectic wetting are confirmed periodically by inspecting random samples and push-testing the attached dice.

11

WIRE BOND

Hermetic: Aluminum wires, ultrasonic bonding.
Molded: Gold wires, thermocompression bonding.

12

QUALITY INSPECTION

Weld strength, bond size and position, wire dress and general workmanship are confirmed periodically by comparing random samples with assembly instructions and quality standards. Bond strength is plotted on statistical control charts, providing early warning of process drifts.

13

INTERNAL VISUAL INSPECTION

Assembled but unsealed units are individually inspected at low and high power.

QUALITY STANDARDS:

All devices – MIL-STD-883, Method 2010, Condition B (latest revision).
Full temperature devices – MIL-M-38510, Para. 3.7 for workmanship (re-bonding limits).

14

QUALITY INSPECTION

Decisions at the 100% inspection are reviewed through periodic random sampling, providing confirmation of product quality and revealing any need for operator retraining.

15a

FINAL SEAL

(Hermetic devices)

15b

ENCAPSULATE

(Molded Devices)

16

HIGH TEMPERATURE STORAGE

MIL-STD-883, Method 1008, Cond. C: 150°C, 24 hr

17

TEMPERATURE CYCLE

MIL-STD-883, Method 1010, Cond. C: -65°C, +150°C, 10 cycles

18

CENTRIFUGE

MIL-STD-883, Method 2001, Cond. E: 30,000 G

19

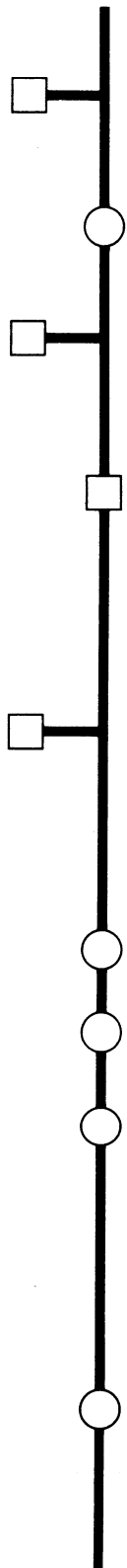
SEAL (HERMETICITY) TEST

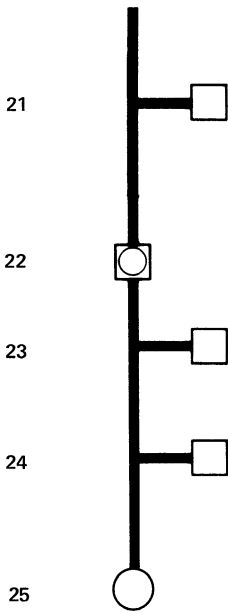
MIL-STD-883, Method 1014, Cond. A or B: Fine Leak
MIL-STD-883, Method 1014, Cond. C2: Gross Leak

20

ELECTRICAL TEST

MIL-STD-883, Method 5004, Para. 3.1.12: Static, dynamic, functional tests at 25°C or in certain products at the most critical extreme temperature to assure accuracy of device selection.





QUALITY GROUP A ELECTRICAL TEST (TABLE I)

MIL-STD-883, Method 5005. See the table below. Quality levels as defined for Class B are applied to both Class B and Class C parts. Proven correlations supported by periodic reconfirmation may be used for some parameters.

MARK, INSPECT, PACK FOR SHIPMENT

QUALITY INSPECTION, PRE-SHIPMENT

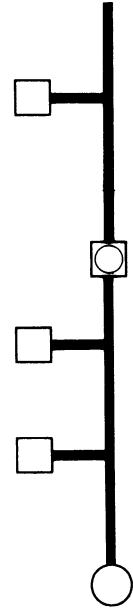
Confirmation of marking, physical quality, and product identity.

QUALITY INSPECTION FOR SHIPMENT RELEASE

Confirmation of product type, count, package.
Confirmation of completion of all process requirements.
Confirmation of required documentation.

SHIP TO CUSTOMER

This AMD standard product meets screening requirements of MIL-STD-883, Class C.



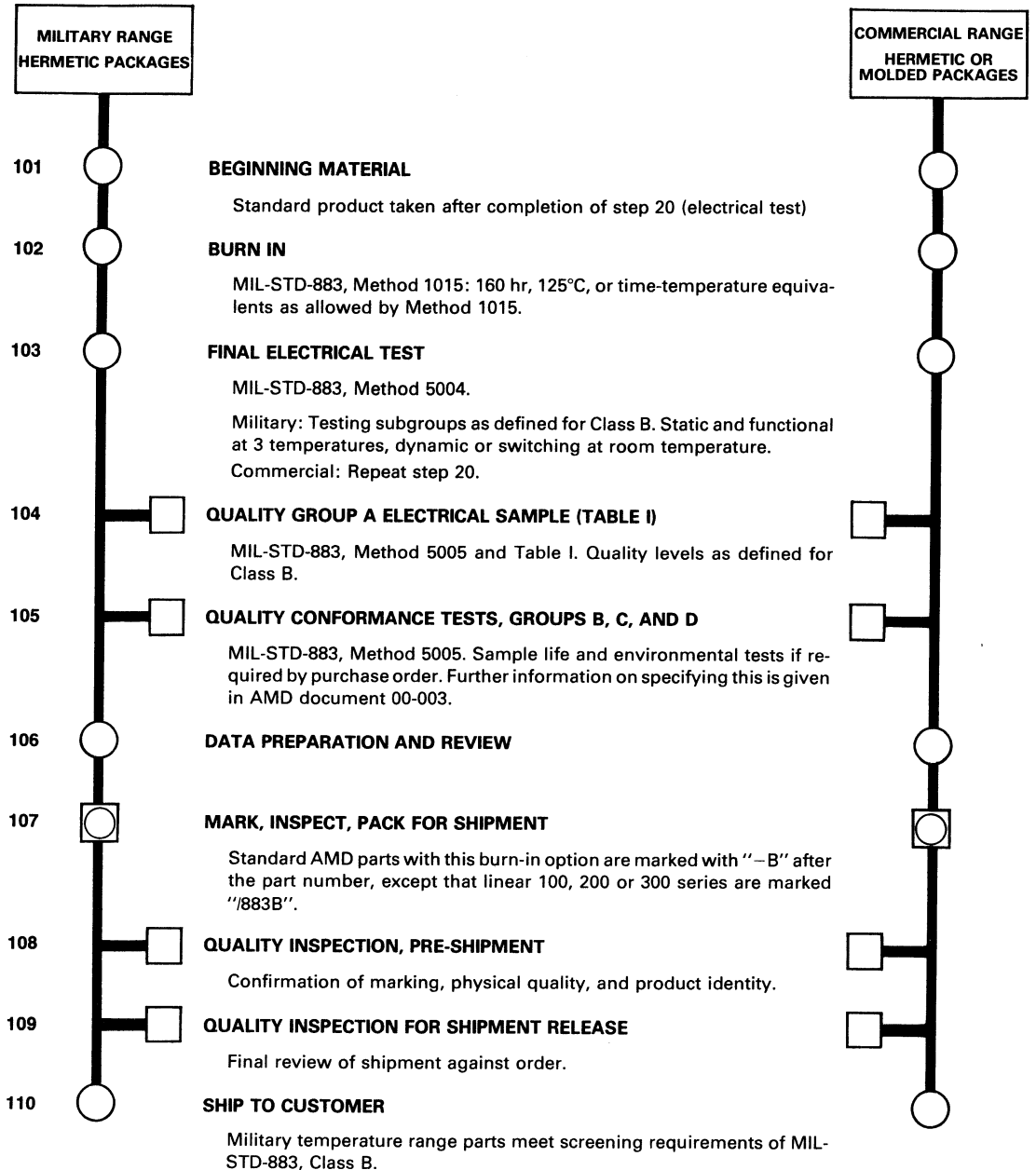
GROUP A ELECTRICAL TESTS
From MIL-STD-883, Method 5005, Table I

Subgroups	LTPD (Note 1)	Initial Sample Size
Subgroup 1 – Static tests at 25°C	5	45
Subgroup 2 – Static tests at maximum rated operating temperature	7	32
Subgroup 3 – Static tests at minimum rated operating temperature	7	32
Subgroup 4 – Dynamic tests at 25°C – Linear devices	5	45
Subgroup 5 – Dynamic tests at maximum rated operating temperature – Linear devices	7	32
Subgroup 6 – Dynamic tests at minimum rated operating temperature – Linear devices	7	32
Subgroup 7 – Functional tests at 25°C	5	45
Subgroup 8 – Functional tests at maximum and minimum rated operating temperatures	10	22
Subgroup 9 – Switching tests at 25°C – Digital devices	7	32
Subgroup 10 – Switching tests at maximum rated operating temperature – Digital devices (Note 2)	10	10
Subgroup 11 – Switching tests at minimum rated operating temperature – Digital devices (Note 2)	10	10

1. Sampling plans are based on LTPD tables of MIL-M-38510. The smaller initial sample size, based on zero rejects allowed, has been chosen unless otherwise indicated. If necessary, the sample size will be increased once to the quantity corresponding to an acceptance number of 2. The minimum reject number in all cases is 3.
2. These subgroups are usually performed during initial device characterization only.

OPTIONAL EXTENDED PROCESSING CLASS B Steps 101 Through 110

Advanced Micro Devices offers several extended processing options to meet customer high-reliability requirements. These are defined in AMD document 00-003. The flow chart below outlines Option B, a 160-hr. burn in. Military temperature range devices processed to this flow (in the left column) meet the screening requirements of MIL-STD-883, Class B.



OTHER OPTIONS

Document 00-003, "Extended Processing Options", further defines Option B as well as other screening or sampling options available or special order. Available options are listed here for reference.

Option	Description	Effect
A	Modified Class A screen (The AMD-A program)	Provides space-grade product, following most Class A requirements of MIL-STD-883, Method 5004.
B	160-hr operating burn in	Upgrades a part from Class C to Class B.
X	Radiographic inspection (X-ray)	Related to Option A. Provides limited internal inspection of sealed parts.
S	Scanning Electron Microscope (SEM) metal inspection	Sample inspection of metal coverage of die.
V	Preseal visual inspection to MIL-STD-883, Method 2010, Cond. A	More stringent visual inspection of assemblies and die surfaces prior to seal.
P	Particle impact noise (PIN) screen with ultrasonic detection.	Detects loose particles of approximately 0.5 mil size or larger, which could affect reliability in zero-G or high vibration applications.
Q	Quality conformance inspection (Group B, C and D life and environmental tests)	Samples from the lot are stressed and tested per Method 5005. The customer's order must state which groups are required. Group B destroys 16 devices; Group C, 92 devices; Group D, 60 devices.

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Hamilton/Avnet Electronics
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Hanover, Maryland 21076
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218 Little Falls Road
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113 Gaither Drive
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Wishire Electronics
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Century Electronics
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